Radiation Report

TPS7H3024-SP Preliminary Total Ionizing Dose (TID)

ABSTRACT

This report discusses the total ionizing dose (TID) parametric results for TPS7H3024-SP, 3V to 14V, four-channel radiation-hardness-assured power-supply supervisor with watchdog. The study was done to determine the TID effects under high dose rate (HDR) up to 100krad(Si). The results show that all samples passed within the specified limits up to 100krad(Si).

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1 Device Information

1.1 Product Description

The TPS7H3024-SP is an integrated, 3V to 14V, four-channel radiation-hardness-assured power-supply supervisor with watchdog. An accurate 599mV ±1% threshold voltage and a 24µA ±3% hysteresis current provide programmable monitoring voltages. A programmable delay time is globally programmed via a single resistor. In addition a PWRGD output is provided to monitor the global power tree status. The device also incorporates a positive edge detection watchdog timer to monitor an external processor for coherent execution. External faults can be propagated to the system by using the SR_UVLO input.

The TPS7H3024-SP is packaged in a 22-pin CFP (ceramic flat package) package. A standard microcircuit drawing (SMD) is available for the QML variant, 5962R2420601VXC.

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1.2 Device Details

Table 1-1 lists the device information used in this TID HDR characterization.

Table 1-1. Device and Exposure Details

TID Exposure Details	
TI Device	TPS7H3024-SP
TI Part Name	5962R2420601VXC
Package	22-pin CFP (HFT)
Technology	LBC7
Quantity Tested	12
Lot Accept/Reject	All levels tested and passed up to 100krad(Si)
HDR Radiation Facility	Texas Instruments, Dallas, TX
HDR Dose Level	50 krad(Si), 100 krad(Si)
HDR Dose Rate	172.519 rads(Si)/s
HDR Radiation Source	Gammacell (Hopewell, GR420) Co-60
Irradiation Temperature	Ambient room temperature

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Figure 1-1. TPS7H3024-SP Device

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2 Total Dose Test Setup

2.1 Test Overview

The TPS7H3024-SP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, Condition A was used. The product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The TPS7H3024-SP HDR exposure was performed on biased and unbiased devices in a Co-60 gamma cell at TI facility in Dallas, Texas. The unattenuated dose rate of this cell is 172.519 rads(Si)/s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and full post-radiation electrical evaluation using Texas Instruments ATE was conducted. ATE test limits are set per data sheet electrical limits based on qualification and characterization data. Post-radiation measurements were taken within 30 minutes of removing the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under HDR exposure were tested in two conditions (biased and unbiased) as described in the following sections.

2.3.1 Unbiased

For the unbiased HDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Figure 2-1 shows the diagram for HDR exposure with biased condition.

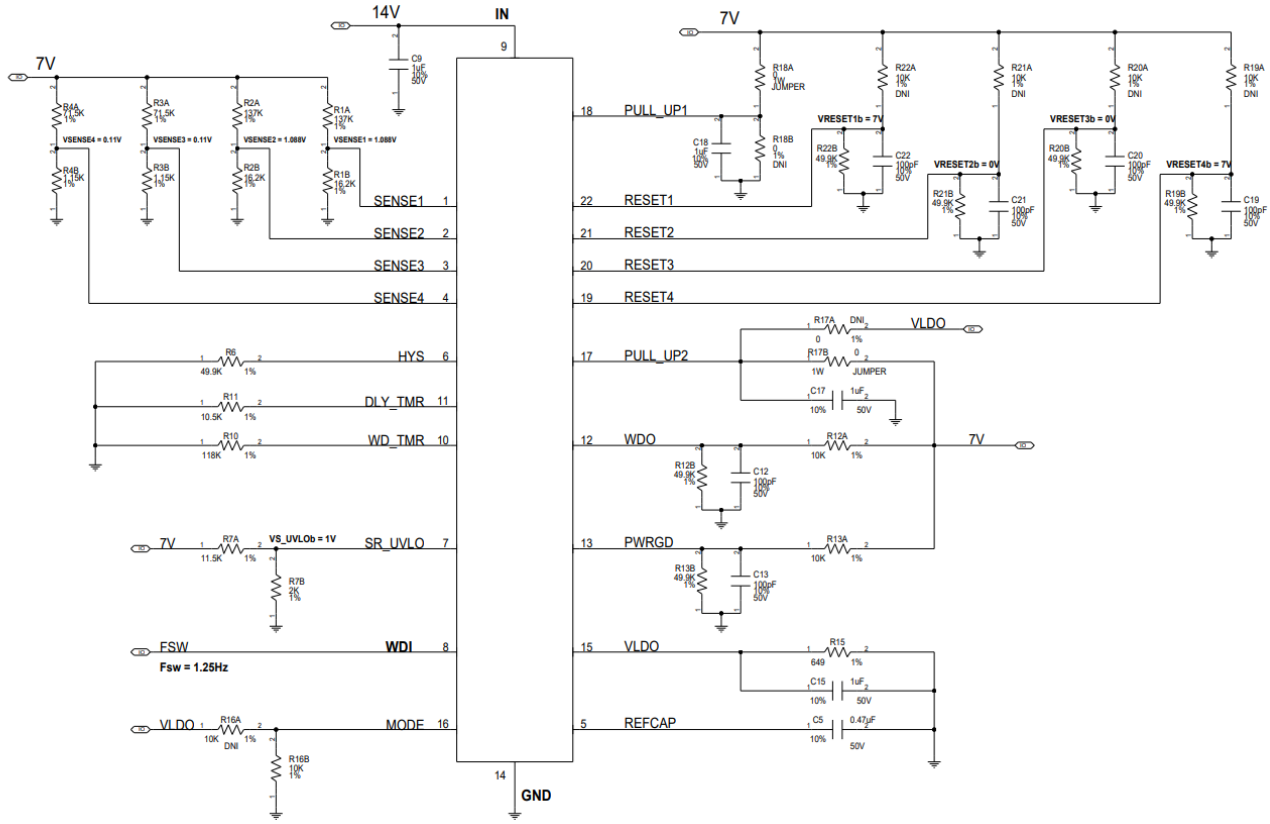

Figure 2-1. Bias Diagram Used in TID Exposure

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2.4 Test Configuration and Condition

HDR devices were stressed at 50krad(Si) and 100krad(Si) for biased and unbiased conditions.

Table 2-1. HDR: 50krad(Si) to 100krad(Si)/s Biased Device Information

Total Samples: 6	
Exposure Levels	
50krad(Si)	100krad(Si)
89, 90, 92	96, 97, 98

Table 2-2. HDR: 50krad(Si) to 100krad(Si)/s Unbiased Device Information

Total Samples: 6	
Exposure Levels	
50krad(Si)	100krad(Si)
93, 94, 95	99, 100, 101

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3 TID Characterization Test Results

3.1 TID Characterization Summary Results

The parametric data for the TPS7H3024-SP passes up to 100krad(Si) HDR TID irradiation. The drifts of the electrical parameters through HDR were within the data sheet limits.

Overall, the TPS7H3024-SP showed a strong degree of hardness to HDR TID irradiation up to 100krad(Si) for both biased and unbiased exposure conditions. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. The parameters that did show a greater degree of change between pre- and post-irradiation were still within the electrical performance characteristics specified in the data sheet electrical parameters. See *TPS7H3024-SP Radiation-Hardness-Assured, 14-V, 4-Channel Supervisor with watchdog* data sheet for the data sheet electrical parameters and associated tests.

See Appendix A for HDR report up to 100krad(Si).

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3.2 Specification Compliance Matrix

3.2.1 Electrical Characteristics

Parameter	Test Conditions	Sub-Group	MIN	TYP	MAX	UNIT	Test Number
SUPPLY VOLTAGES AND CURRENTS							
V_{IN} quiescent current	$\overline{RESETx}$ = Low and High, $V_{SR_\overline{UVLO}} > V_{TH_SR_\overline{UVLO}_RISING}$ (MAX)	1, 2, 3		1.5	2.5	mA	6.4, 6.5, 6.6, 6.7
V_{IN} shutdown current	$V_{SR_\overline{UVLO}} = 0$	1, 2, 3		1.5	2.1		6.0 and 6.1
V_{IN} rising undervoltage lockout		1, 2, 3	2.73	2.8	2.88	V	6.137
V_{IN} falling undervoltage lockout		1, 2, 3	2.58	2.65	2.72		6.138
Internal linear regulator output voltage	4V ≤ V_{IN} ≤ 14V	1, 2, 3	3.23	3.29	3.37	V	6.9 and 6.10
	V_{IN} < 3V	1, 2, 3	98%	99%		× V_{IN}	6.8
VLDO maximum current for out of regullation operation	3.65V ≤ VIN ≤ 14V, VLDO= 98.5% x $VLDO_{(NOM)}$	1, 2, 3			5	mA	6.11, 6.12
Internal bandgap voltage		1, 2, 3	1.188	1.2	1.212	V	6.13 and 6.14
IN power on reset voltage	1.6V ≤ V_{PULL_UPx} ≤ 7V, V_{OL} ≤ 320mV with $I_{\overline{RESETx}}$ = –1mA	1, 2, 3		1.42	2		6.139, 6.140, 6.141, 6.142, 6.143, 6.144, 6.145, 6.146, 6.147, 6.148
PULL_UPx power on reset voltage	V_{IN} = 0V, V_{OL} ≤ 320mV with $I_{\overline{RESETx}}$ = –100µA	1, 2, 3		0.85	1.1		6.149, 6.150, 6.151, 6.152, 6.153
V_{HYS}	R_{HYS} = 49.9kΩ	1, 2, 3	1.164	1.2	1.236		6.155
SENSE1 TO SENSE4, UP AND $\overline{DOWN}$ COMPARATOR INPUTS							
Threshold voltage at SENSEx		1, 2, 3	593.1	599.7	604.9	mV	13.1, 13.2, 13.3, 13.4, 13.5, 13.6, 13.7, 13.8, 13.9, 13.10, 13.11, 13.12, 13.13, 13.14, 13.15, 13.16, 13.17, 13.18, 13.19, 13.20, 13.21, 13.22, 13.23, 13.24, 13.25, 13.26, 13.27, 13.28, 13.29, 13.30, 13.31, 13.32
SENSEx hysteresis current	V_{SENSEx} = 700mV	1, 2, 3	23.28	24	24.72	µA	6.25, 6.26, 6.27, 6.28, 6.29, 6.30, 6.31, 6.32
Input leakage current at SENSEx	V_{SENSEx} = 500mV	1, 2, 3		1	100	nA	6.17, 6.18, 6.19, 6.20, 6.21, 6.22, 6.23, 6.24
Rising threshold voltage at $\overline{SR_SVLO}$		1, 2, 3	580	602	618	mV	13.33, 13.36, 13.39, 13.42
Falling threshold voltage at $\overline{SR_SVLO}$		1, 2, 3	475	499	517		13.34, 13.37, 13.40, 13.43
Input leakage current at $\overline{SR_SVLO}$	$V_{SR_\overline{UVLO}}$ = 7V	1, 2, 3		2	100	nA	6.15 and 6.16
Rising threshold voltage at WDI		1, 2, 3	578	602	624	mV	13.45
Falling threshold voltage at WDI		1, 2, 3	473	498	521	mV	13.46
Input leakage current at WDI	V_{WDI} = 7V	1, 2, 3		1.4	100	nA	6.37 and 6.38

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3.2.1 Electrical Characteristics (continued)

Parameter	Test Conditions		Sub-Group	MIN	TYP	MAX	UNIT	Test Number
Rising threshold voltage at MODE			1, 2, 3	576	600	623	mV	13.48
Falling threshold voltage at MODE			1, 2, 3	475	498	520	mV	13.49
Input leakage current at MODE	V_{MODE} = 7V		1, 2, 3		1	100	nA	6.39 and 6.40
$\overline{RESET1}$ TO $\overline{RESET4}$, PWRGD AND $\overline{WDO}$ PUSH PULL OUTPUTS								
PULL_UPx leakage current	**V_{PULL_UPx} = 7V, $\overline{RESETx}$ = LOW**		**1, 2, 3**		**48**	**100**	**µA**	6.33, 6.34, 6.35, 6.36
Low-level $\overline{RESETx}$ output voltage	1.6V ≤ V_{PULL_UP1} ≤ 7V	I_{LOAD} = –2mA	1, 2, 3			5%	x V_{PULL_UP1}	6.65, 6.66, 6.67, 6.68, 6.71, 6.72, 6.73, 6.74, 6.77, 6.78, 6.79, 6.80, 6.83, 6.84, 6.85, 6.86
		I_{LOAD} = –10mA	1, 2, 3			23%		6.113, 6.114, 6.115, 6.116, 6.119, 6.120, 6.121, 6.122, 6.125, 6.126, 6.127, 6.128, 6.131, 6.132, 6.133, 6.134
High-level $\overline{RESETx}$ output voltage	1.6V ≤ V_{PULL_UP1} ≤ 7V	I_{LOAD} = 2mA	1, 2, 3	95%				6.41, 6.42, 6.43, 6.44, 6.47, 6.48, 6.49, 6.50, 6.53, 6.54, 6.55, 6.56, 6.59, 6.60, 6.61, 6.62
		I_{LOAD} = 10mA	1, 2, 3	75%				6.89, 6.90, 6.91, 6.92, 6.95, 6.96, 6.97, 6.98, 6.101, 6.102, 6.103, 6.104, 6.107, 6.108, 6.109, 6.110
Low-level PWRGD output voltage	1.6V ≤ V_{PULL_UP2} ≤ 7V	I_{LOAD} = –2mA	1, 2, 3			5%	x V_{PULL_UP2}	6.70, 6.76, 6.82, 6.88
		I_{LOAD} = –10mA	1, 2, 3			23%		6.118, 6.124, 6.130, 6.136
High-level PWRGD output voltage	1.6V ≤ V_{PULL_UP2} ≤ 7V	I_{LOAD} = 2mA	1, 2, 3	95%				6.46, 6.52, 6,58, 6.64
		I_{LOAD} = 10mA	1, 2, 3	75%				6.94, 6.100, 6.106, 6.112
Low-level $\overline{WDO}$ output voltage	1.6V ≤ V_{PULL_UP2} ≤ 7V	I_{LOAD} = –2mA	1, 2, 3			5%		6.69, 6.75, 6.81, 6.87
		I_{LOAD} = –10mA	1, 2, 3			23%		6.117, 6.123, 6.129, 6.135
High-level $\overline{WDO}$ output voltage	1.6V ≤ V_{PULL_UP2} ≤ 7V	I_{LOAD} = 2mA	1, 2, 3	95%				6.45, 6.51, 6.57, 6.63
		I_{LOAD} = 10mA	1, 2, 3	75%				6.93, 6.99, 6.105, 6.111

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3.2.1 Electrical Characteristics (continued)

Parameter	Test Conditions		Sub-Group	MIN	TYP	MAX	UNIT	Test Number
$\overline{\text{RESET}}$x rising output voltage slew rate	10% to 90% of V_{PULL_UP1}, R_{LOAD} = 50kΩ, C_{LOAD} = 100pF	1.6V ≤ V_{PULL_UP1} ≤ 7V	9, 10, 11	17	298		V/µs	19.0, 19.1, 19.2, 19.3, 19.12, 19.13, 19.14, 19.15, 19.24, 19.25, 19.26, 19.27, 19.36, 19.37, 19.38, 19.39
PWRGD rising output voltage slew rate			9, 10, 11	17	298			19.4, 19.16, 19.28, 19.40
$\overline{\text{WDO}}$ rising output voltage slew rate			9, 10, 11	17	298			19.5, 19.17, 19.29, 19.41
$\overline{\text{RESET}}$x falling output voltage slew rate	90% to 10% of V_{PULL_UP1}, R_{LOAD} = 50kΩ, C_{LOAD} = 100pF	1.6V ≤ V_{PULL_UP1} ≤ 7V	9, 10, 11	44	186			19.6, 19.7, 19.8, 19.9, 19.18, 19.19, 19.20, 19.21, 19.30, 19.31, 19.32, 19.33, 19.42, 19.43, 19.44, 19.45
PWRGD falling output voltage slew rate			9, 10, 11	44	186			19.10, 19.22, 19.34, 19.46
$\overline{\text{WDO}}$ falling output voltage slew rate			9, 10, 11	44	186			19.11, 19.23, 19.35, 19.47
$\overline{\text{RESET}}$ PMOS source output resistance	I_{LOAD} = 2mA	1.6V ≤ V_{PULL_UP1} ≤ 3.3V	1, 2, 3		20	40	Ω	18.0, 18.1, 18.2, 18.3, 18.6, 18.7, 18.8, 18.9
		3.3V ≤ V_{PULL_UP1} ≤ 7V	1, 2, 3		9	20		18.12, 18.13, 18.14, 18.15, 18.18, 18.19, 18.20, 18.21
PWRGD PMOS source output resistance	I_{LOAD} = 2mA	1.6V ≤ V_{PULL_UP2} ≤ 3.3V	1, 2, 3		20	40		18.4, 18.10
		3.3V ≤ V_{PULL_UP2} ≤ 7V	1, 2, 3		9	20		18.16, 18.22
$\overline{\text{WDO}}$ PMOS source output resistance	I_{LOAD} = 2mA	1.6V ≤ V_{PULL_UP2} ≤ 3.3V	1, 2, 3		20	40		18.5, 18.11
		3.3V ≤ V_{PULL_UP2} ≤ 7V	1, 2, 3		9	20		18.17, 18.23
$\overline{\text{RESET}}$ NMOS sink output resistance	I_{LOAD} = –2mA, 1.6V ≤ V_{PULL_UP1} ≤ 7V		1, 2, 3		16	36		18.24, 18.25, 18.26, 18.27, 18.30, 18.31, 18.32, 18.33, 18.36, 18.37, 18.38, 18.39, 18.42, 18.43, 18.44, 18.45
PWRGD NMOS sink output resistance	I_{LOAD} = –2mA, 1.6V ≤ V_{PULL_UP1} ≤ 7V		1, 2, 3		16	36		18.28, 18.34, 18.40, 18.46
$\overline{\text{WDO}}$ NMOS sink output resistance	I_{LOAD} = –2mA, 1.6V ≤ V_{PULL_UP1} ≤ 7V		1, 2, 3		16	36		18.29, 18.35, 18.41, 18.47

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3.2.1 Electrical Characteristics (continued)

Parameter	Test Conditions	Sub-Group	MIN	TYP	MAX	UNIT	Test Number
THERMAL PROTECTION							
Thermal shutdown enter temperature				185		℃	
Thermal shutdown exit temperature				171			
DELAY AND WATCHDOG TIMERS							
Delay time	R_{DLY_TMR} = 10.5kΩ	1, 2, 3	0.22	0.26	0.33	ms	5.20, 5.21, 5.23, 5.24, 5.25, 5.38, 5.39, 5.41, 5.42, 5.43, 5.56, 5.57, 5.59, 5.60, 5.61, 5.74, 5.75, 5.77, 5.78, 5.79
	R_{DLY_TMR} = 619kΩ	1, 2, 3	11.3	12.5	13.7		5.26, 5.27, 5.29, 5.30, 5.31, 5.44, 5.45, 5.47, 5.48, 5.49, 5.62, 5.63, 5.65, 5.66, 5.67, 5.80, 5.81, 5.83, 5.84, 5.85
	R_{DLY_TMR} = 1.18MΩ	1, 2, 3	21.3	23.7	26.2		5.32, 5.33, 5.35, 5.36, 5.37, 5.50, 5.51, 5.53, 5.54, 5.55, 5.68, 5.69, 5.71, 5.72, 5.73, 5.86, 5.87, 5.89, 5.90, 5.91
Watchdog time-out	R_{WD_TMR} = 56.2kΩ	1, 2, 3	0.43	0.52	0.57	s	5.22, 5.40, 5.58, 5.76
	R_{WD_TMR} = 118kΩ	1, 2, 3	0.8	1	1.2		5.28, 5.46, 5.64, 5.82
	R_{WD_TMR} = 174kΩ	1, 2, 3	1.34	1.5	1.7		5.34, 5.52, 5.70, 5.88

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3.2.2 Timing Requirements

Parameter	Test Conditions		Sub-Group	MIN	TYP	MAX	UNIT	Test Number
Start-up delay time	$V_{REFCAP} \geq 1.1V$		1, 2, 3		0.3	2.8	ms	6.154
$\overline{RESET}$ propagation delay	DLY_TMR = Open, $V_{OVERDRIVE}$ = 10mV, SR_{SENSEx} = 27V/µs, from 50% of SENSEx to 50% of $\overline{RESET}$x		1, 2, 3		0.62	4.3	µs	5.0, 5.1, 5.3, 5.4, 5.5, 5.6, 5.8, 5.9, 5.10, 5.11, 5.13, 5.14, 5.15, 5.16, 5.18, 5.19
PWRGD propagation delay	DLY_TMR = Open, $V_{OVERDRIVE}$ = 10mV, SR_{SENSEx} = 27V/µs, from 50% of V_{SENSEx} to 50% of V_{PWRGD}		1, 2, 3		0.51	4.3	µs	5.2, 5.7, 5.12, 5.17
SR_$\overline{UVLO}$ propagation delay	$V_{SR_\overline{FAULT}}$ = Falling from 1V to 0V in 10ns, V_{SENSEx} = 610mV, from 50% of $V_{SR_\overline{UVLO}}$ to 50% of V_{PWRGD}		1, 2, 3		0.92	2	µs	5.104, 5.105, 5.106, 5.107, 5.108, 5.109, 5.110, 5.111
WDI propagation delay	V_{WDI} = Rising from 0V to 1V in 10ns, VSENSEx = 610mV, from 50% of V_{WDI} to 50% of V_{WDO}	t_{WD_TMR} = 0.5s	1, 2, 3		23	40	µs	
		t_{WD_TMR} = 1s			47	80		
		t_{WD_TMR} = 1.5s			68	116		
WDI minimum pulse width			4, 5, 6	2			× t_{WD_OSC}	25.11, 25.12, 25.13, 25.14, 25.15, 25.16
SR_UVLO minimum pulse width for valid reset			4, 5, 6		0.61	1.1	µs	25.1, 25.2
VSENSEx hold time for valid fault detection		C_{LOAD} = 100pF, $V_{OVERDRIVE}$ = |100mV|	4, 5, 6		0.56	2.2	µs	25.3, 25.4, 25.5, 25.6, 25.7, 25.8, 25.9, 25.10
Rising threshold on VSENSEx hold time			4, 5, 6			3.7	µs	

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4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H3024-SP Radiation-Hardness-Assured, 14-V, 4-Channel Supervisor with Watchdog*, data sheet.
- Texas Instruments, *TPS7H3024EVM-CVAL Evaluation Module User's Guide*, user's guide.

4.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

A Appendix: HDR TID Report Data

This appendix contains the HDR TID report data.

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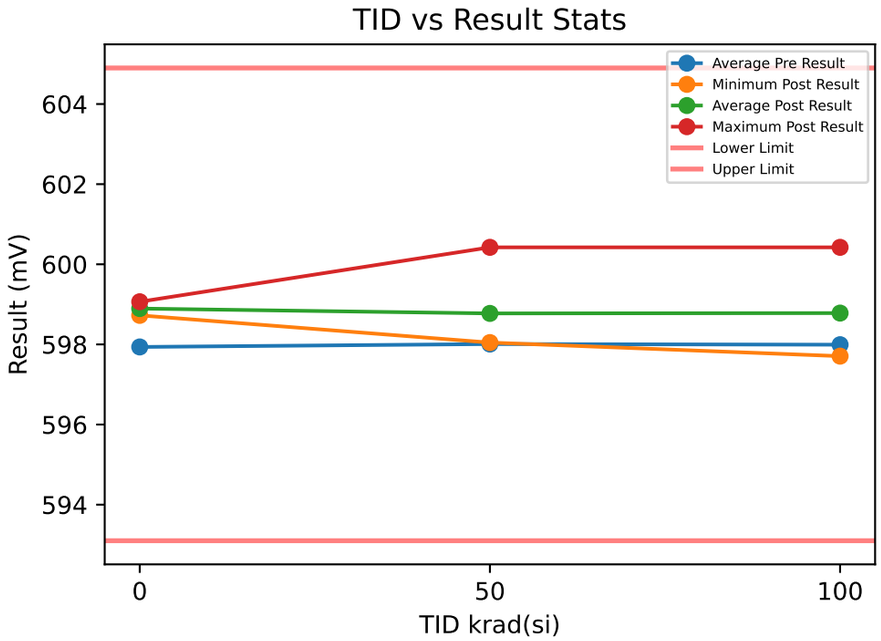
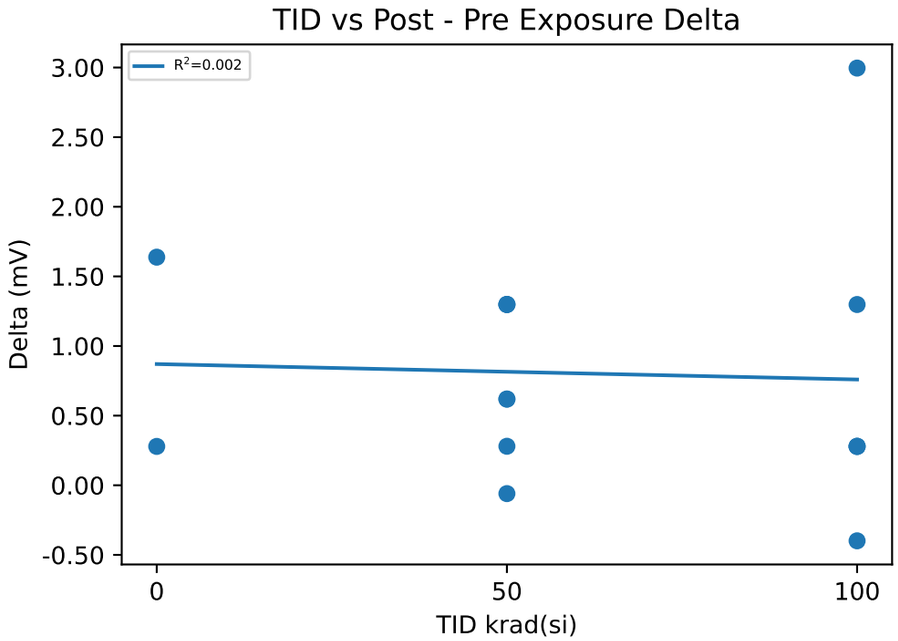
Device Test: 13.1 VTH_SENSE(VTH_SENSE1_RISING/SENSE1/1.6/3/0/0/0/@VTH_SENSE)





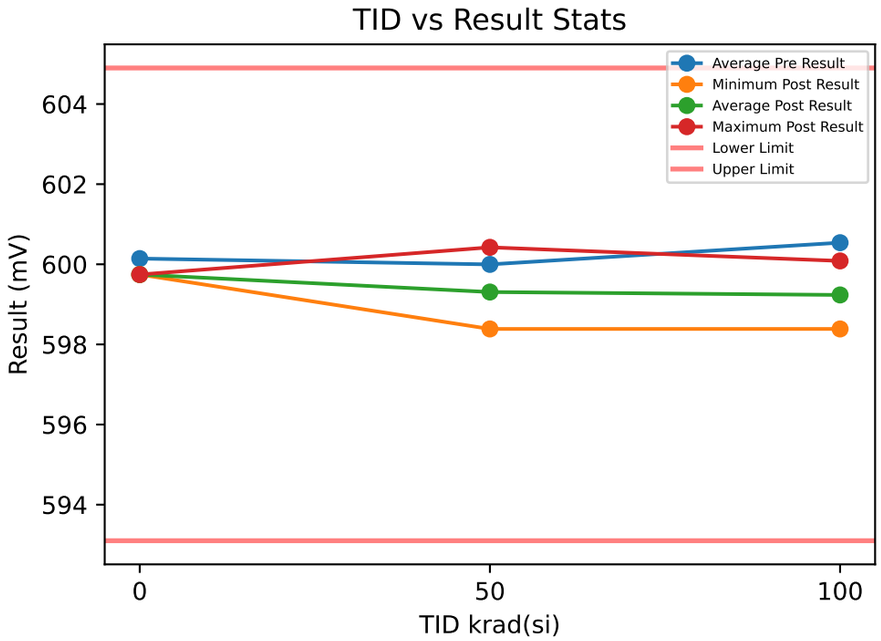
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

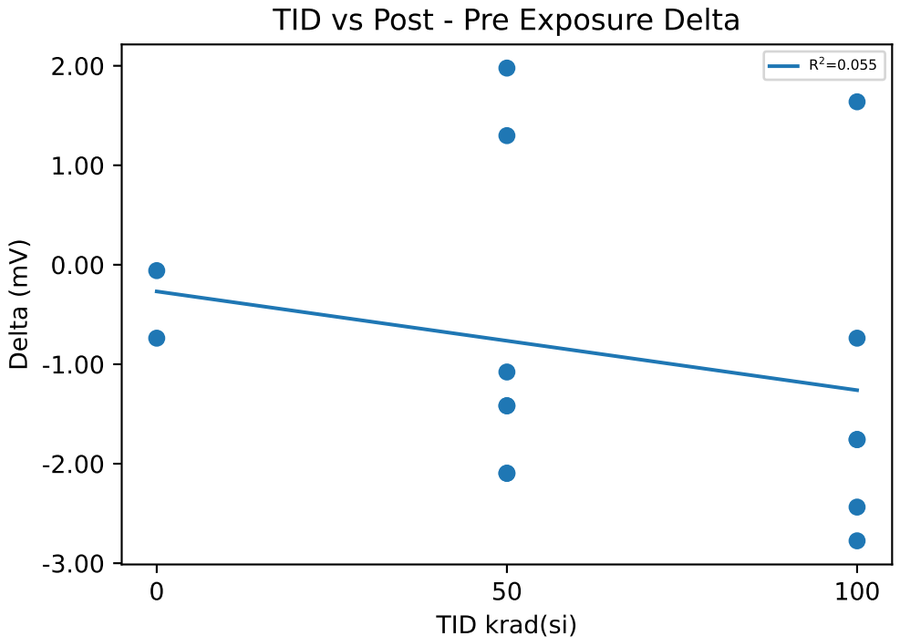
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	597.43	598.73	1.298
89	50	Biased	597.77	598.39	0.619
90	50	Biased	598.78	598.73	-0.06
92	50	Biased	598.11	598.39	0.28
93	50	Unbiased	597.43	598.05	0.619
94	50	Unbiased	599.12	600.42	1.299
95	50	Unbiased	597.43	598.73	1.298
96	100	Biased	598.11	597.71	-0.399
97	100	Biased	597.77	598.05	0.279
98	100	Biased	598.78	599.07	0.28
99	100	Unbiased	597.43	598.73	1.298
100	100	Unbiased	597.43	600.42	2.996
101	100	Unbiased	598.45	598.73	0.279
102	0	Correlation	597.43	599.07	1.638
103	0	Correlation	598.45	598.73	0.279

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	597.43	597.94	598.45	0.72054	598.73	598.89	599.07	0.24042	0.279	0.9585	1.638	0.96096
50	597.43	598.01	599.12	0.69875	598.05	598.77	600.42	0.77001	-0.06	0.76471	1.299	0.54952
100	597.43	597.99	598.78	0.55444	597.71	598.78	600.42	0.94623	-0.399	0.78883	2.996	1.21

Device Test: 13.10 VTH_SENSE(VTH_SENSE1_FALLING/SENSE1/7/3/0/0/0/@VTH_SENSE)





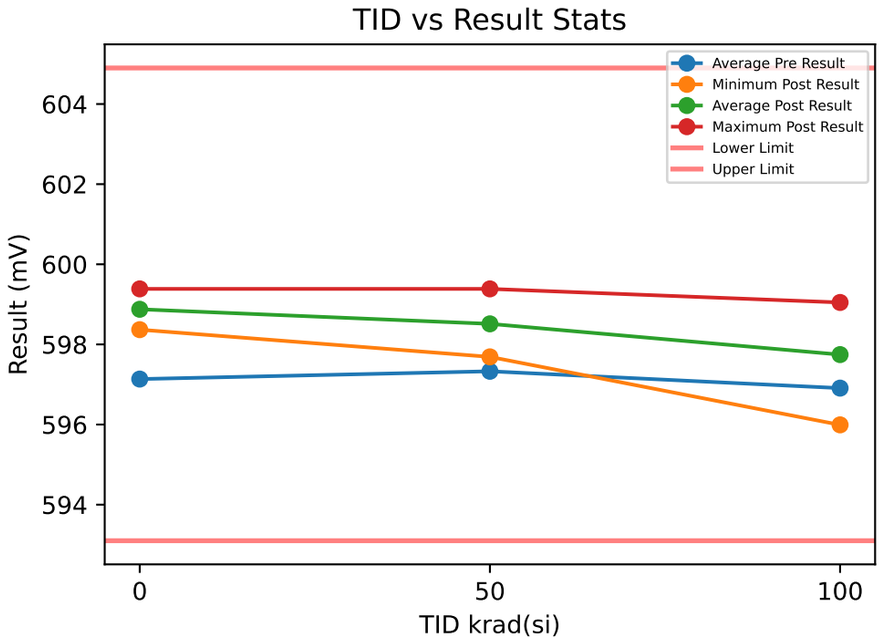
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

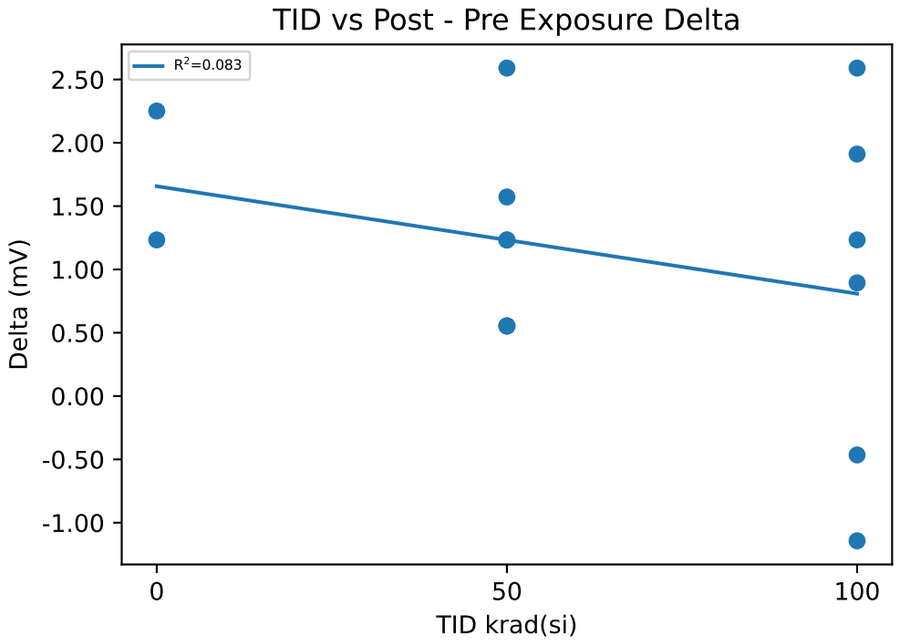
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	599.8	598.73	-1.078
89	50	Biased	601.84	599.74	-2.096
90	50	Biased	601.84	600.42	-1.417
92	50	Biased	600.14	598.73	-1.418
93	50	Unbiased	600.48	598.39	-2.096
94	50	Unbiased	598.45	600.42	1.977
95	50	Unbiased	597.43	598.73	1.298
96	100	Biased	601.16	598.39	-2.775
97	100	Biased	600.48	598.73	-1.757
98	100	Biased	598.11	599.74	1.638
99	100	Unbiased	601.5	599.74	-1.757
100	100	Unbiased	600.82	600.08	-0.738
101	100	Unbiased	601.16	598.73	-2.436
102	0	Correlation	599.8	599.74	-0.059
103	0	Correlation	600.48	599.74	-0.738

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	599.8	600.14	600.48	0.48013	599.74	599.74	599.74	0	-0.738	-0.3985	-0.059	0.48013
50	597.43	600	601.84	1.638	598.39	599.31	600.42	0.87047	-2.096	-0.69	1.977	1.6446
100	598.11	600.54	601.5	1.2411	598.39	599.23	600.08	0.70427	-2.775	-1.3042	1.638	1.602

Device Test: 13.11 VTH_SENSE(VTH_SENSE2_RISING/SENSE2/7/3/0/0/0/@VTH_SENSE)





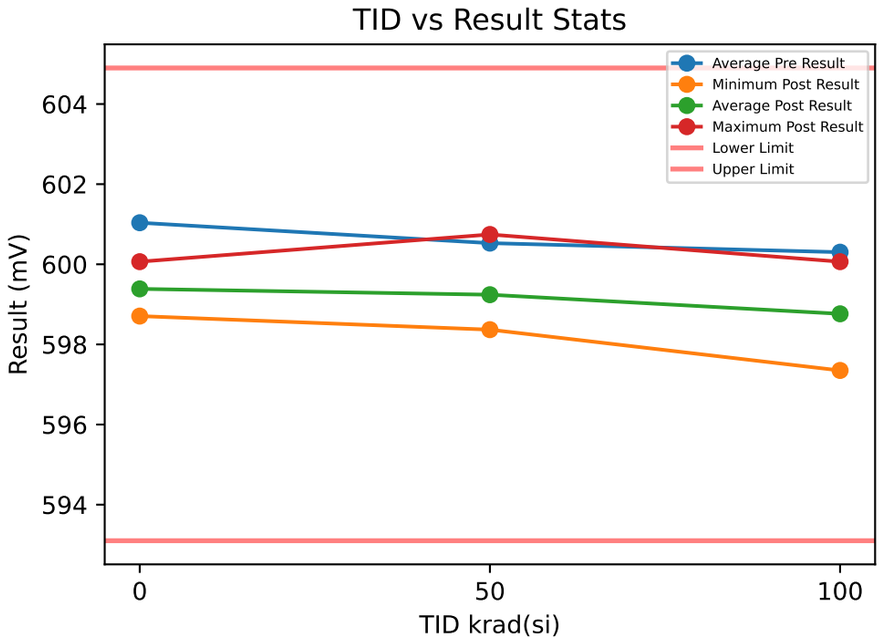
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

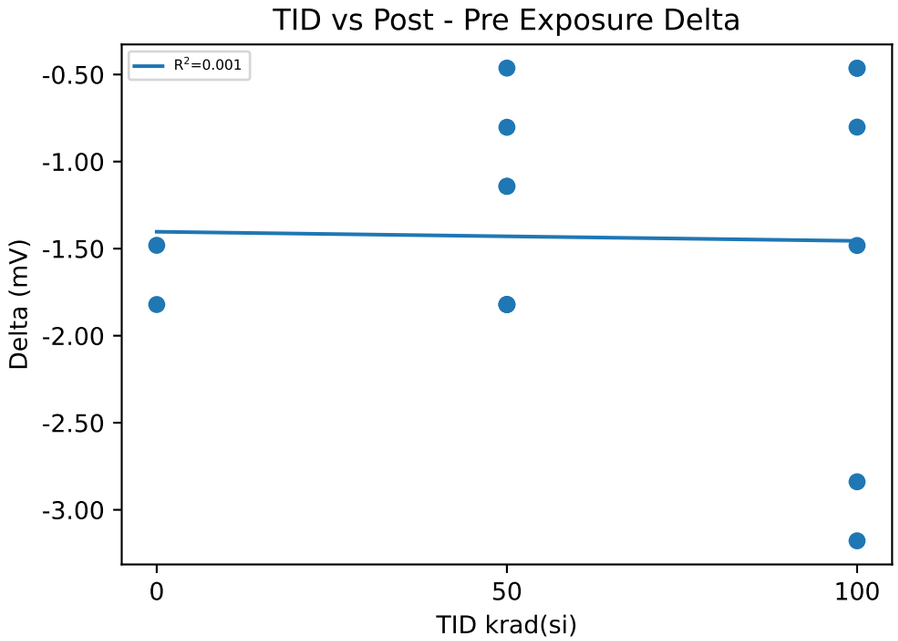
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	595.78	598.37	2.59
89	50	Biased	597.81	598.37	0.554
90	50	Biased	597.81	599.05	1.233
92	50	Biased	597.48	598.03	0.553
93	50	Unbiased	597.13	597.69	0.554
94	50	Unbiased	597.81	599.39	1.572
95	50	Unbiased	597.48	598.71	1.232
96	100	Biased	596.12	597.35	1.233
97	100	Biased	597.13	595.99	-1.143
98	100	Biased	598.15	599.05	0.894
99	100	Unbiased	596.12	598.71	2.59
100	100	Unbiased	596.46	598.37	1.911
101	100	Unbiased	597.48	597.01	-0.465
102	0	Correlation	596.12	598.37	2.251
103	0	Correlation	598.15	599.39	1.233

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	596.12	597.13	598.15	1.4397	598.37	598.88	599.39	0.71983	1.233	1.742	2.251	0.71983
50	595.78	597.33	597.81	0.72933	597.69	598.51	599.39	0.58326	0.553	1.184	2.59	0.74432
100	596.12	596.91	598.15	0.82192	595.99	597.75	599.05	1.1643	-1.143	0.83667	2.59	1.4144

Device Test: 13.12 VTH_SENSE(VTH_SENSE2_FALLING/SENSE2/7/3/0/0/0/@VTH_SENSE)





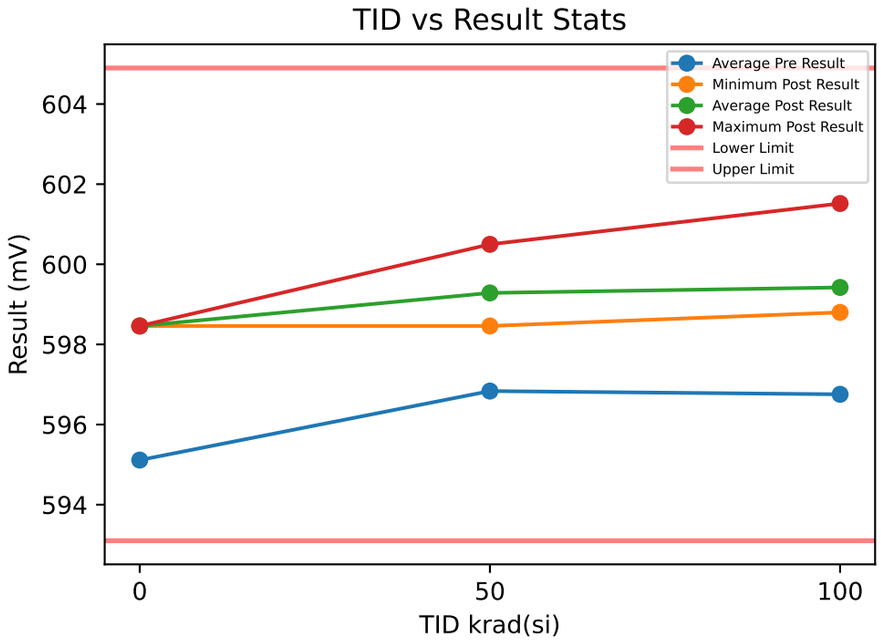
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

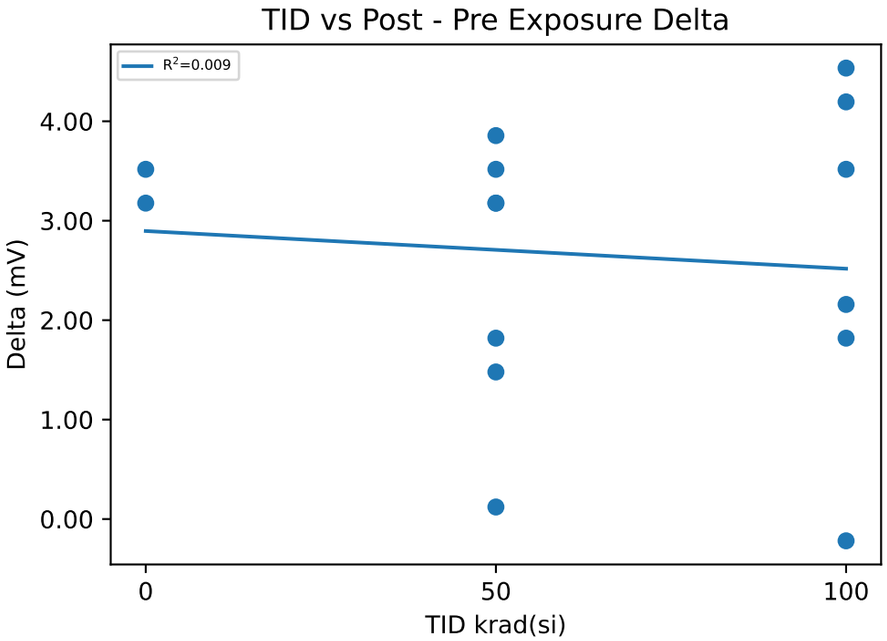
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	599.51	598.37	-1.142
89	50	Biased	600.53	599.73	-0.803
90	50	Biased	601.21	599.39	-1.821
92	50	Biased	600.53	598.71	-1.821
93	50	Unbiased	600.19	598.37	-1.821
94	50	Unbiased	601.21	600.74	-0.463
95	50	Unbiased	600.53	599.39	-1.142
96	100	Biased	600.87	597.69	-3.178
97	100	Biased	599.85	598.37	-1.482
98	100	Biased	600.87	600.07	-0.802
99	100	Unbiased	599.85	599.39	-0.464
100	100	Unbiased	600.19	599.73	-0.464
101	100	Unbiased	600.19	597.35	-2.839
102	0	Correlation	600.53	598.71	-1.821
103	0	Correlation	601.55	600.07	-1.481

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	600.53	601.04	601.55	0.71983	598.71	599.39	600.07	0.96025	-1.821	-1.651	-1.481	0.24042
50	599.51	600.53	601.21	0.58784	598.37	599.24	600.74	0.85095	-1.821	-1.2876	-0.463	0.54936
100	599.85	600.3	600.87	0.46316	597.35	598.76	600.07	1.1238	-3.178	-1.5382	-0.464	1.2028

Device Test: 13.13 VTH_SENSE(VTH_SENSE3_RISING/SENSE3/7/3/0/0/0/@VTH_SENSE)





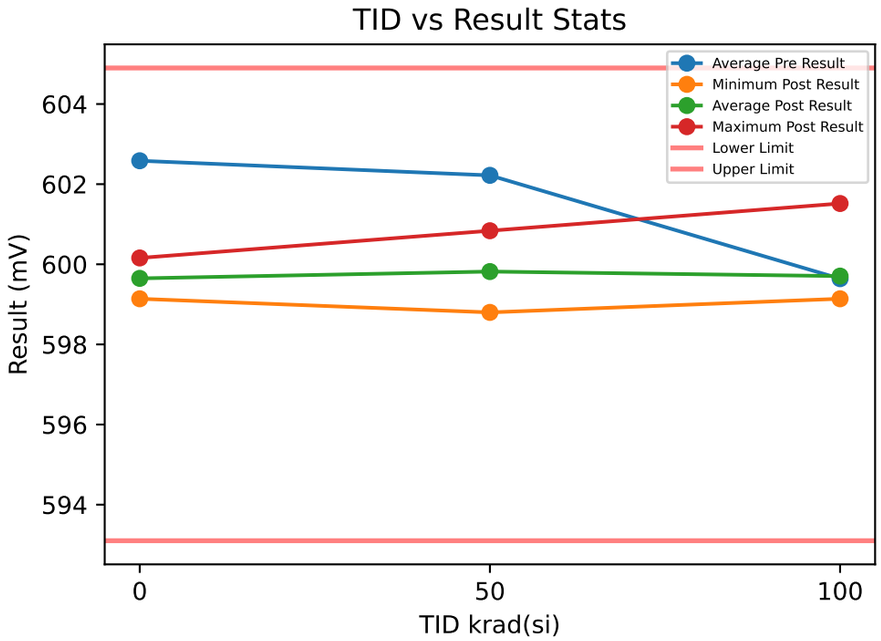
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

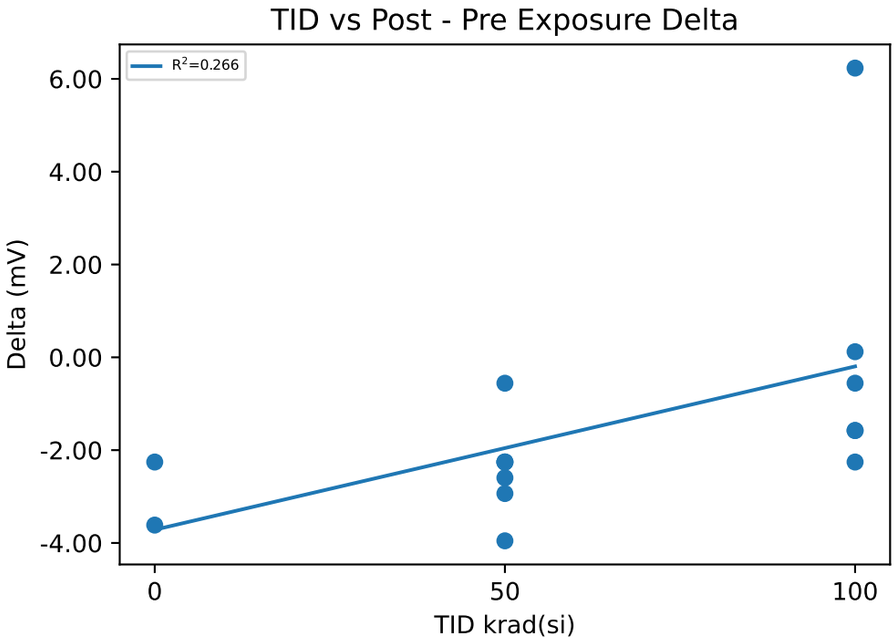
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	594.94	598.8	3.856
89	50	Biased	598	599.48	1.479
90	50	Biased	598.68	600.5	1.819
92	50	Biased	595.62	599.14	3.517
93	50	Unbiased	599.02	599.14	0.121
94	50	Unbiased	596.3	599.48	3.177
95	50	Unbiased	595.28	598.46	3.177
96	100	Biased	597.32	599.14	1.819
97	100	Biased	599.02	598.8	-0.219
98	100	Biased	598	601.52	3.517
99	100	Unbiased	594.6	599.14	4.535
100	100	Unbiased	594.6	598.8	4.195
101	100	Unbiased	596.98	599.14	2.158
102	0	Correlation	594.94	598.46	3.517
103	0	Correlation	595.28	598.46	3.177

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	594.94	595.11	595.28	0.24042	598.46	598.46	598.46	0	3.177	3.347	3.517	0.24042
50	594.94	596.84	599.02	1.6964	598.46	599.28	600.5	0.64628	0.121	2.4494	3.856	1.3502
100	594.6	596.75	599.02	1.8053	598.8	599.42	601.52	1.0398	-0.219	2.6675	4.535	1.7807

Device Test: 13.14 VTH_SENSE(VTH_SENSE3_FALLING/SENSE3/7/3/0/0/0/@VTH_SENSE)





Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

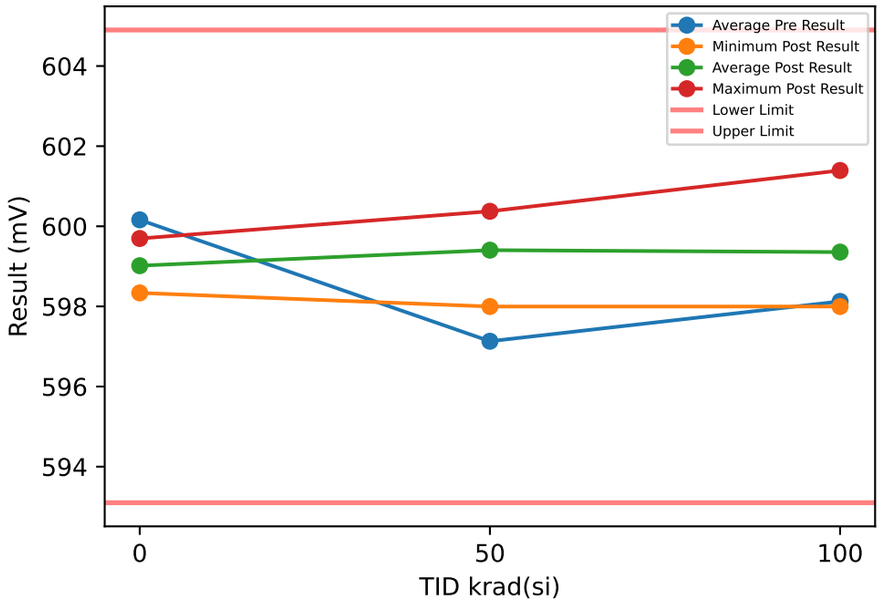
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	601.74	599.48	-2.256
89	50	Biased	600.72	600.16	-0.558
90	50	Biased	603.09	600.84	-2.256
92	50	Biased	603.43	600.5	-2.935
93	50	Unbiased	601.39	599.14	-2.256
94	50	Unbiased	603.77	599.82	-3.954
95	50	Unbiased	601.39	598.8	-2.596
96	100	Biased	593.59	599.82	6.233
97	100	Biased	601.39	599.14	-2.256
98	100	Biased	602.07	601.52	-0.557
99	100	Unbiased	600.72	599.14	-1.577
100	100	Unbiased	601.06	599.48	-1.577
101	100	Unbiased	599.02	599.14	0.121
102	0	Correlation	602.75	599.14	-3.615
103	0	Correlation	602.41	600.16	-2.256

Test Statistics (mV)

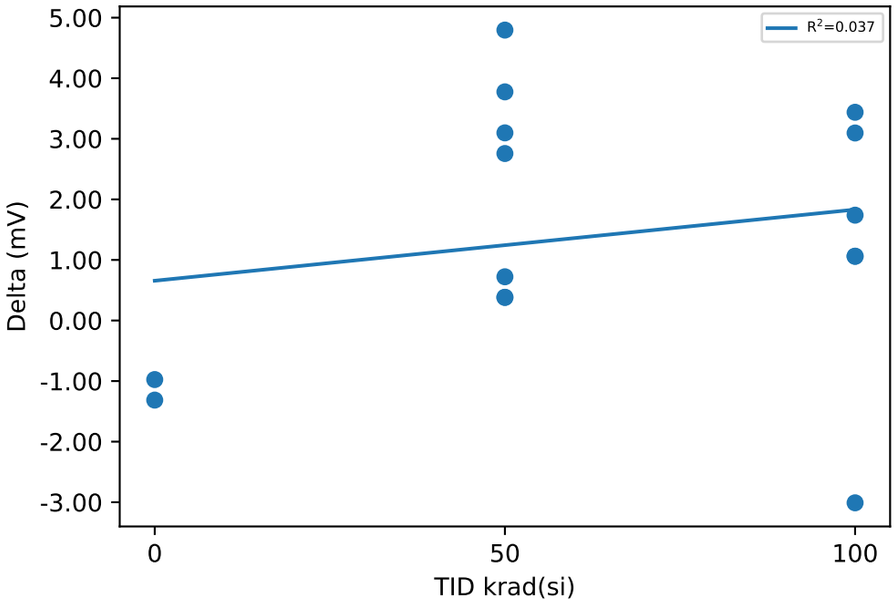
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	602.41	602.58	602.75	0.24042	599.14	599.65	600.16	0.72054	-3.615	-2.9355	-2.256	0.96096
50	600.72	602.22	603.77	1.1903	598.8	599.82	600.84	0.73379	-3.954	-2.4016	-0.558	1.0161
100	593.59	599.64	602.07	3.1374	599.14	599.71	601.52	0.92825	-2.256	0.0645	6.233	3.1373

Device Test: 13.15 VTH_SENSE(VTH_SENSE4_RISING/SENSE4/7/3/0/0/0/@VTH_SENSE)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



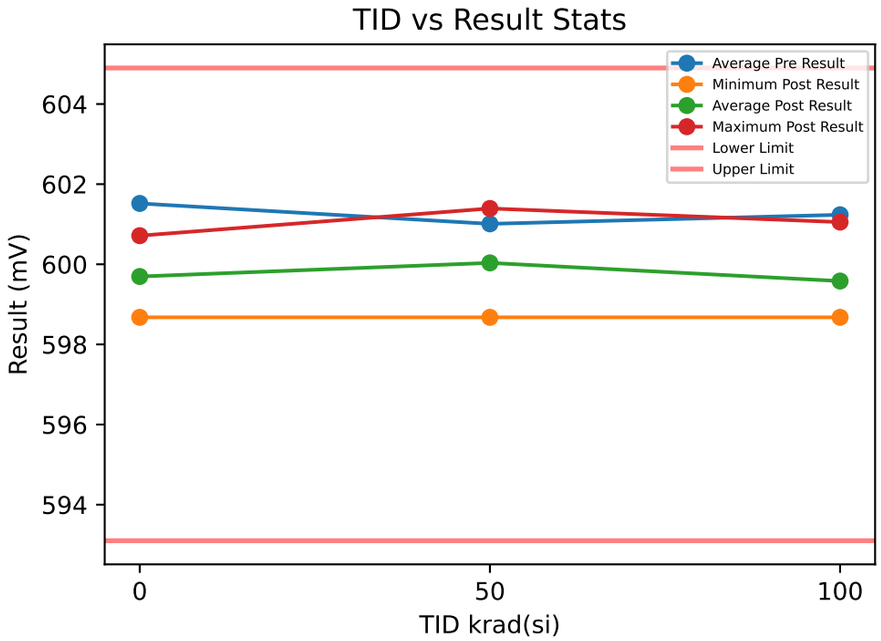
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

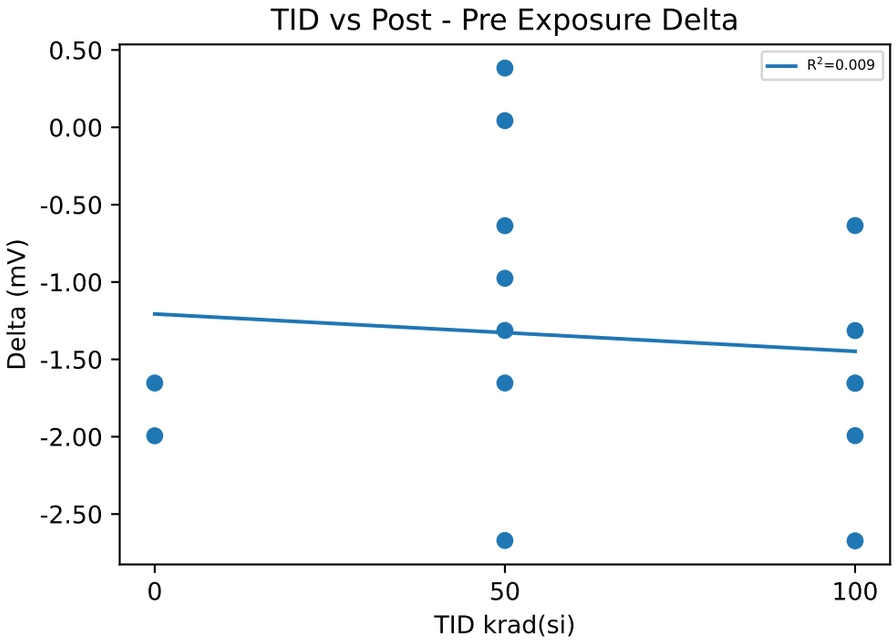
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	595.58	600.37	4.795
89	50	Biased	598.97	599.7	0.722
90	50	Biased	597.28	600.37	3.098
92	50	Biased	598.63	599.02	0.382
93	50	Unbiased	594.22	598	3.775
94	50	Unbiased	599.31	599.7	0.383
95	50	Unbiased	595.92	598.68	2.757
96	100	Biased	597.28	598.34	1.061
97	100	Biased	597.96	599.02	1.061
98	100	Biased	597.96	601.39	3.438
99	100	Unbiased	594.9	598	3.096
100	100	Unbiased	603.04	600.03	-3.01
101	100	Unbiased	597.62	599.36	1.739
102	0	Correlation	599.31	598.34	-0.975
103	0	Correlation	601.01	599.7	-1.314

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	599.31	600.16	601.01	1.2	598.34	599.02	599.7	0.96025	-1.314	-1.1445	-0.975	0.23971
50	594.22	597.13	599.31	1.9481	598	599.4	600.37	0.88613	0.382	2.2731	4.795	1.7835
100	594.9	598.12	603.04	2.6698	598	599.36	601.39	1.2338	-3.01	1.2308	3.438	2.3087

Device Test: 13.16 VTH_SENSE(VTH_SENSE4_FALLING/SENSE4/7/3/0/0/0/@VTH_SENSE)





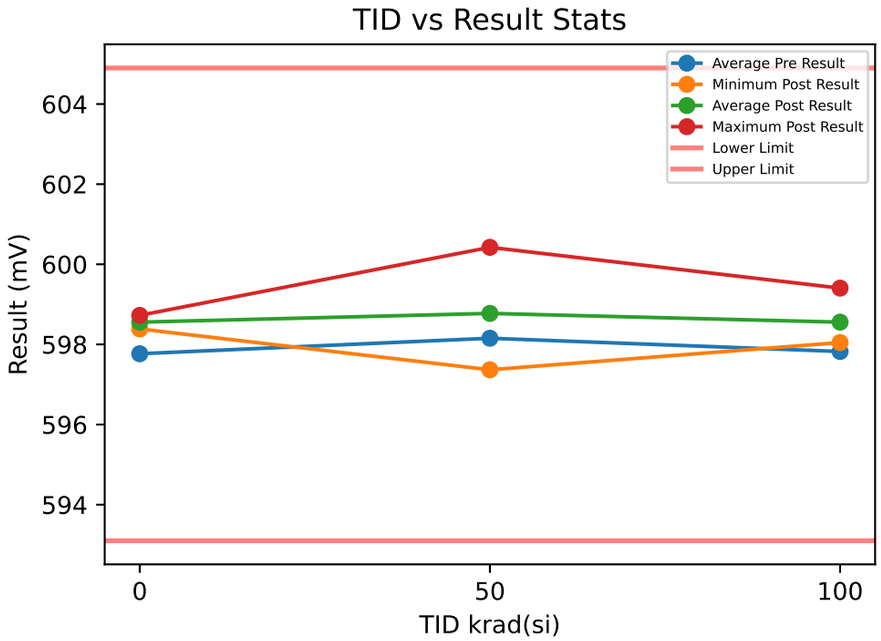
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

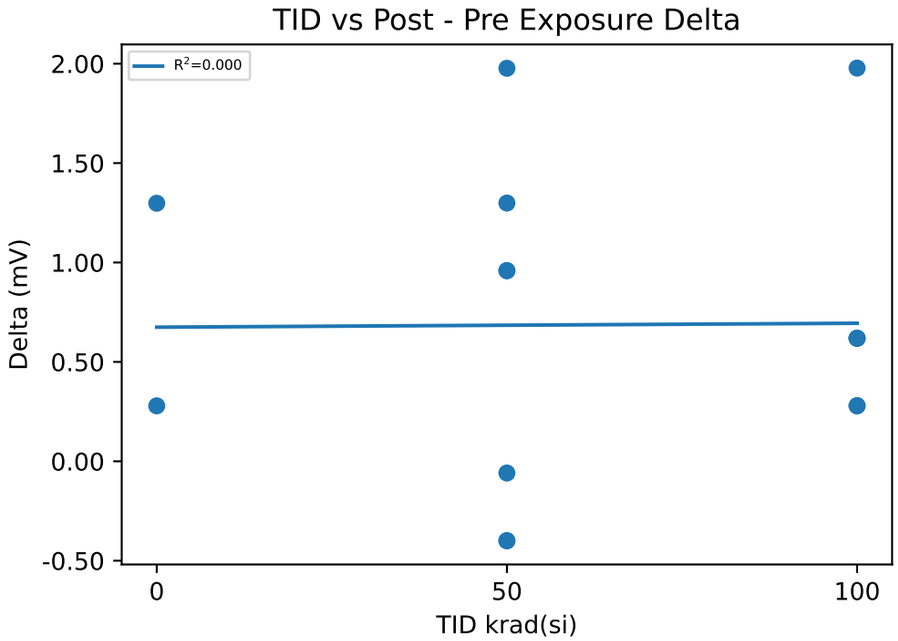
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	600.67	601.05	0.383
89	50	Biased	602.71	600.03	-2.671
90	50	Biased	602.37	600.71	-1.653
92	50	Biased	599.99	599.36	-0.636
93	50	Unbiased	598.97	599.02	0.043
94	50	Unbiased	602.71	601.39	-1.313
95	50	Unbiased	599.65	598.68	-0.976
96	100	Biased	601.35	598.68	-2.673
97	100	Biased	600.67	599.02	-1.654
98	100	Biased	602.37	601.05	-1.314
99	100	Unbiased	600.33	598.68	-1.654
100	100	Unbiased	602.37	600.37	-1.993
101	100	Unbiased	600.33	599.7	-0.635
102	0	Correlation	600.67	598.68	-1.994
103	0	Correlation	602.37	600.71	-1.653

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	600.67	601.52	602.37	1.2	598.68	599.7	600.71	1.4411	-1.994	-1.8235	-1.653	0.24112
50	598.97	601.01	602.71	1.5675	598.68	600.03	601.39	1.0559	-2.671	-0.97471	0.383	1.0365
100	600.33	601.24	602.37	0.95217	598.68	599.58	601.05	0.97631	-2.673	-1.6538	-0.635	0.6793

Device Test: 13.17 VTH_SENSE(VTH_SENSE1_RISING/SENSE1/1.6/14/0/0/0/@VTH_SENSE)





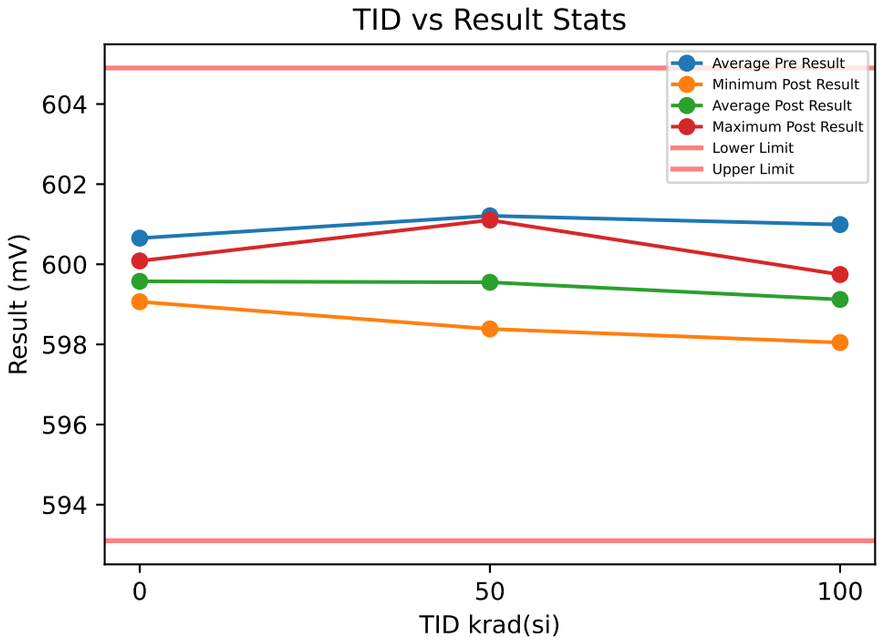
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

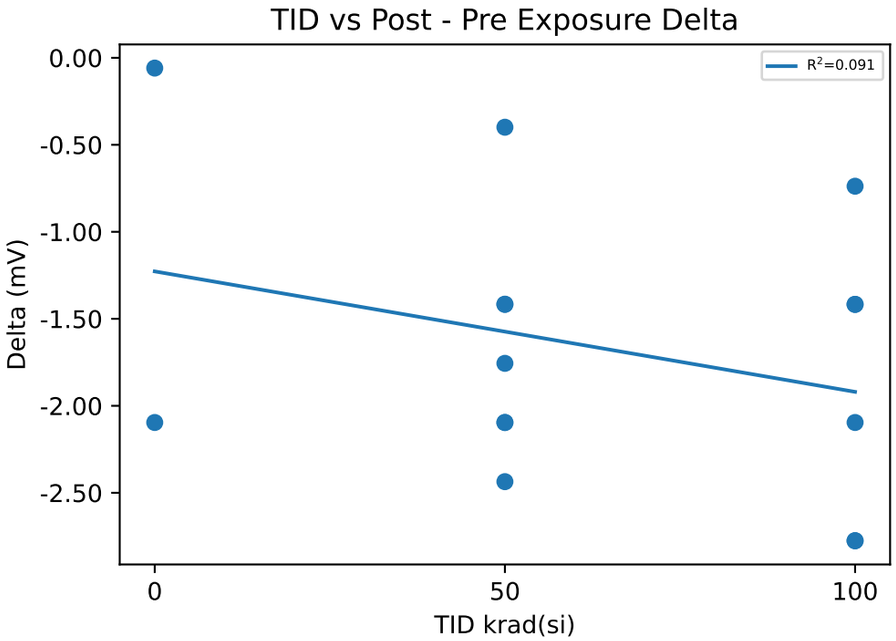
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	597.09	599.07	1.977
89	50	Biased	598.11	597.71	-0.399
90	50	Biased	599.46	599.4	-0.059
92	50	Biased	597.43	598.39	0.959
93	50	Unbiased	597.77	597.37	-0.4
94	50	Unbiased	599.12	600.42	1.299
95	50	Unbiased	598.11	599.07	0.959
96	100	Biased	597.77	598.39	0.619
97	100	Biased	597.77	598.05	0.279
98	100	Biased	598.11	598.73	0.619
99	100	Unbiased	597.77	598.39	0.619
100	100	Unbiased	597.43	599.4	1.978
101	100	Unbiased	598.11	598.39	0.28
102	0	Correlation	597.09	598.39	1.298
103	0	Correlation	598.45	598.73	0.279

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	597.09	597.77	598.45	0.96025	598.39	598.56	598.73	0.23971	0.279	0.7885	1.298	0.72054
50	597.09	598.15	599.46	0.86374	597.37	598.77	600.42	1.0453	-0.4	0.61943	1.977	0.91943
100	597.43	597.82	598.11	0.2555	598.05	598.56	599.4	0.46822	0.279	0.73233	1.978	0.63251

Device Test: 13.18 VTH_SENSE(VTH_SENSE1_FALLING/SENSE1/1.6/14/0/0/0/@VTH_SENSE)





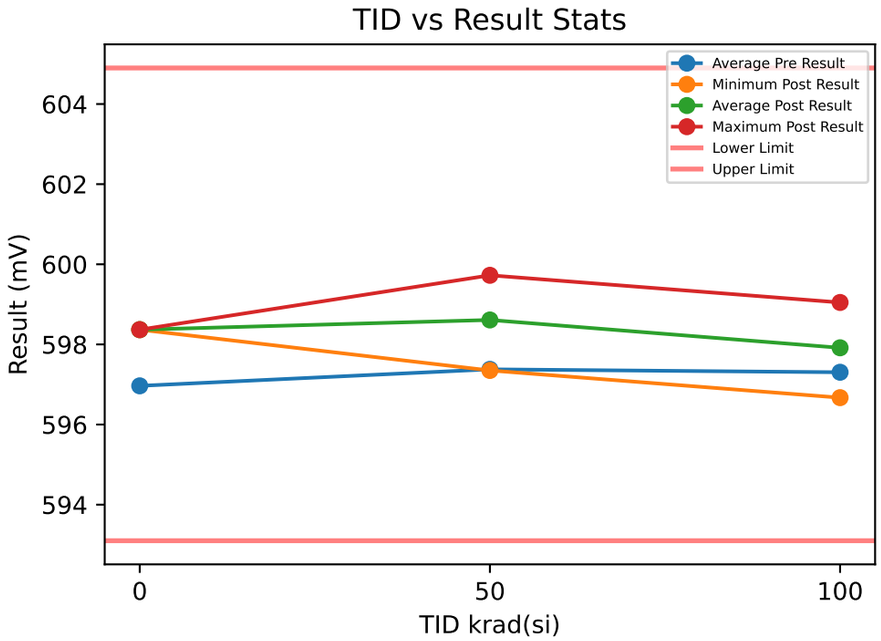
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

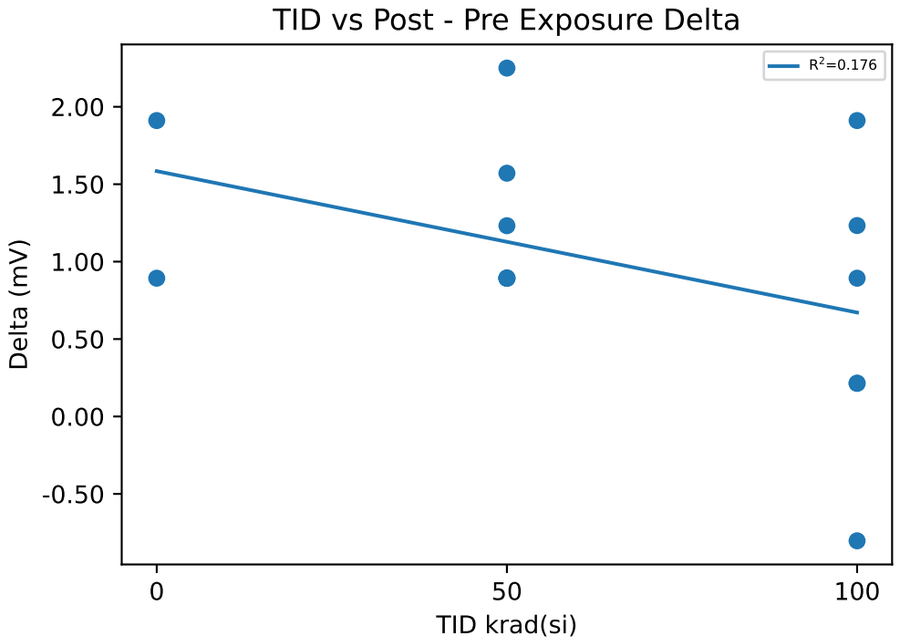
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	600.14	599.74	-0.399
89	50	Biased	601.5	599.4	-2.096
90	50	Biased	602.52	601.1	-1.416
92	50	Biased	600.82	599.4	-1.417
93	50	Unbiased	600.48	598.39	-2.096
94	50	Unbiased	601.84	600.08	-1.756
95	50	Unbiased	601.16	598.73	-2.436
96	100	Biased	601.16	598.39	-2.775
97	100	Biased	600.82	598.05	-2.776
98	100	Biased	601.16	599.74	-1.417
99	100	Unbiased	600.14	599.4	-0.738
100	100	Unbiased	601.16	599.74	-1.417
101	100	Unbiased	601.5	599.4	-2.096
102	0	Correlation	600.14	600.08	-0.059
103	0	Correlation	601.16	599.07	-2.096

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	600.14	600.65	601.16	0.71983	599.07	599.57	600.08	0.72054	-2.096	-1.0775	-0.059	1.4404
50	600.14	601.21	602.52	0.81818	598.39	599.55	601.1	0.89556	-2.436	-1.6594	-0.399	0.67086
100	600.14	600.99	601.5	0.46786	598.05	599.12	599.74	0.72573	-2.776	-1.8698	-0.738	0.82253

Device Test: 13.19 VTH_SENSE(VTH_SENSE2_RISING/SENSE2/1.6/14/0/0/0/@VTH_SENSE)





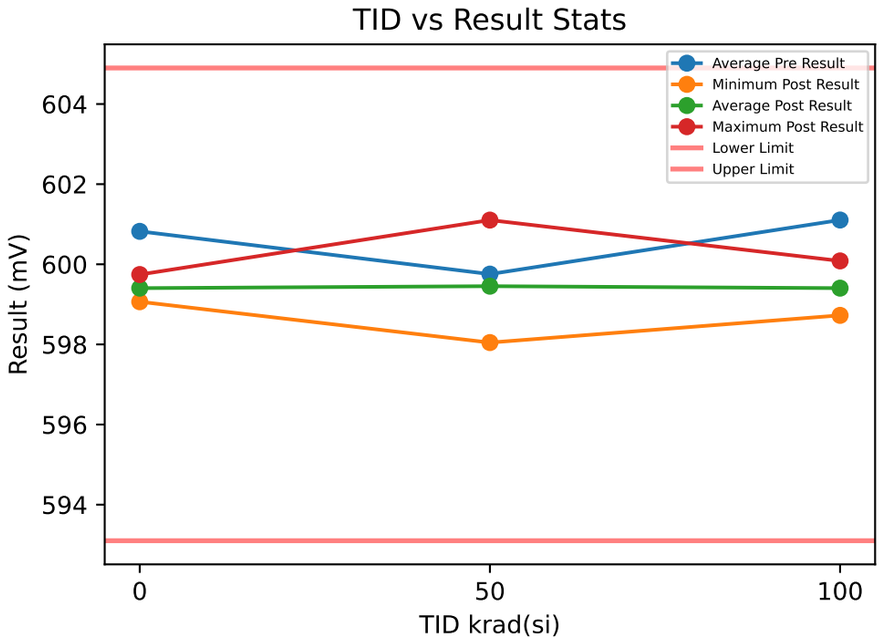
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

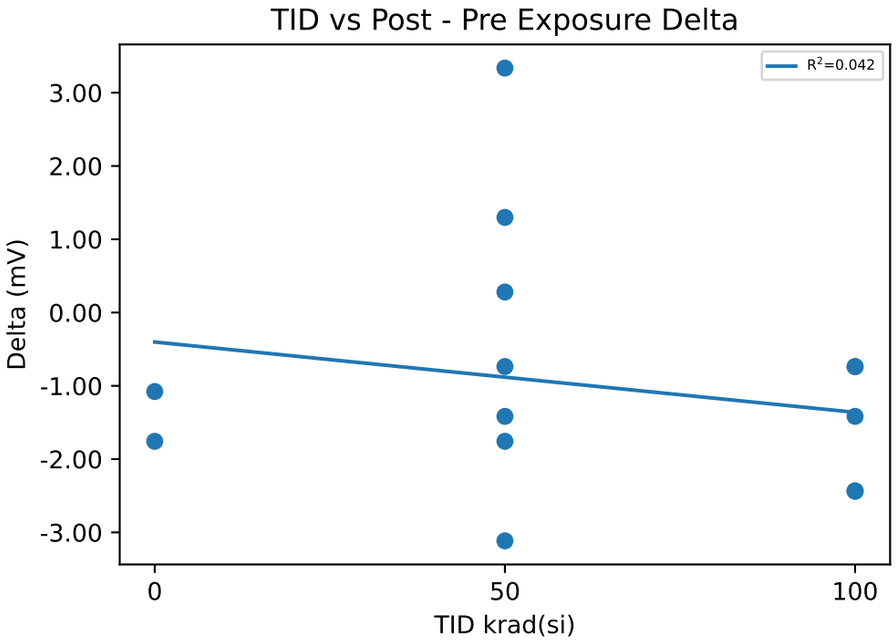
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	596.46	598.03	1.571
89	50	Biased	598.49	599.39	0.893
90	50	Biased	597.48	599.73	2.25
92	50	Biased	596.46	597.35	0.893
93	50	Unbiased	597.13	598.03	0.893
94	50	Unbiased	598.15	599.05	0.894
95	50	Unbiased	597.48	598.71	1.232
96	100	Biased	596.46	596.67	0.214
97	100	Biased	597.13	597.35	0.215
98	100	Biased	597.81	599.05	1.233
99	100	Unbiased	596.46	598.37	1.911
100	100	Unbiased	599.51	598.71	-0.803
101	100	Unbiased	596.46	597.35	0.893
102	0	Correlation	596.46	598.37	1.911
103	0	Correlation	597.48	598.37	0.893

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	596.46	596.97	597.48	0.71983	598.37	598.37	598.37	0	0.893	1.402	1.911	0.71983
50	596.46	597.38	598.49	0.77655	597.35	598.61	599.73	0.84763	0.893	1.2323	2.25	0.51805
100	596.46	597.3	599.51	1.2089	596.67	597.92	599.05	0.92735	-0.803	0.6105	1.911	0.94554

Device Test: 13.2 VTH_SENSE(VTH_SENSE1_FALLING/SENSE1/1.6/3/0/0/0/@VTH_SENSE)





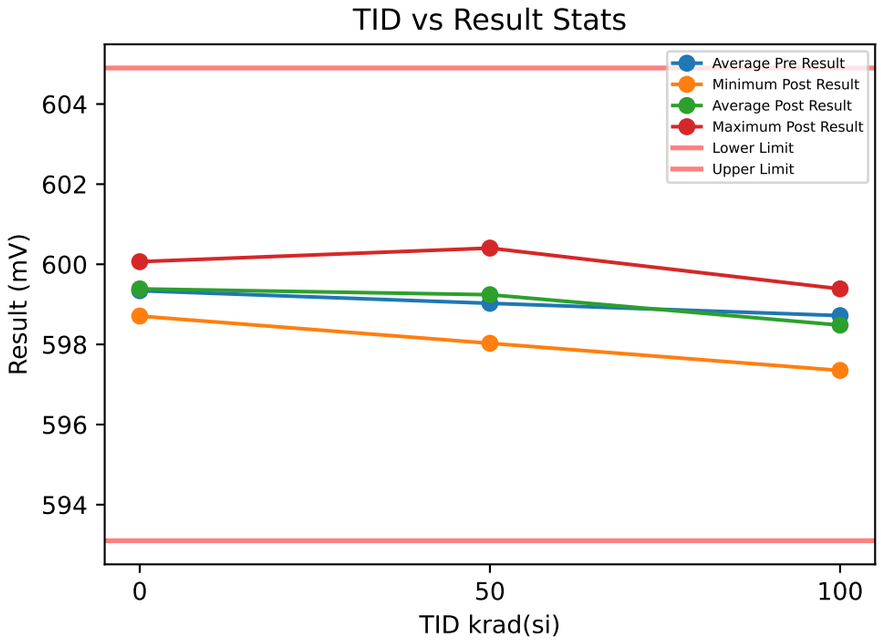
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

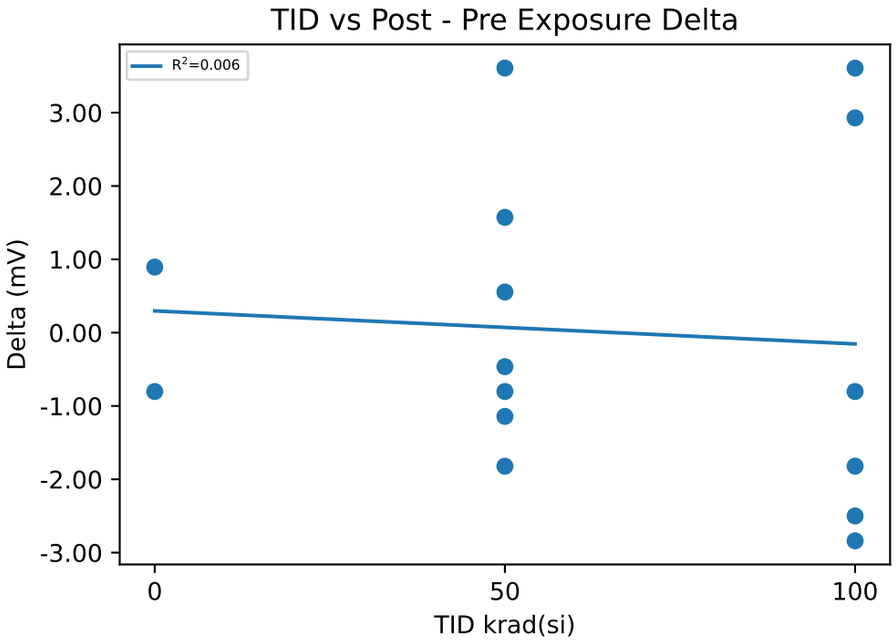
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	597.77	599.07	1.298
89	50	Biased	601.16	599.74	-1.417
90	50	Biased	601.84	601.1	-0.737
92	50	Biased	600.82	599.07	-1.757
93	50	Unbiased	601.16	598.05	-3.115
94	50	Unbiased	596.75	600.08	3.336
95	50	Unbiased	598.78	599.07	0.28
96	100	Biased	601.16	598.73	-2.436
97	100	Biased	601.16	598.73	-2.436
98	100	Biased	601.16	599.74	-1.417
99	100	Unbiased	600.82	600.08	-0.738
100	100	Unbiased	600.82	600.08	-0.738
101	100	Unbiased	601.5	599.07	-2.436
102	0	Correlation	600.14	599.07	-1.078
103	0	Correlation	601.5	599.74	-1.757

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	600.14	600.82	601.5	0.96025	599.07	599.4	599.74	0.48013	-1.757	-1.4175	-1.078	0.48013
50	596.75	599.75	601.84	1.9738	598.05	599.45	601.1	0.96925	-3.115	-0.30171	3.336	2.1446
100	600.82	601.1	601.5	0.2555	598.73	599.4	600.08	0.64458	-2.436	-1.7002	-0.738	0.84333

Device Test: 13.20 VTH_SENSE(VTH_SENSE2_FALLING/SENSE2/1.6/14/0/0/0/@VTH_SENSE)





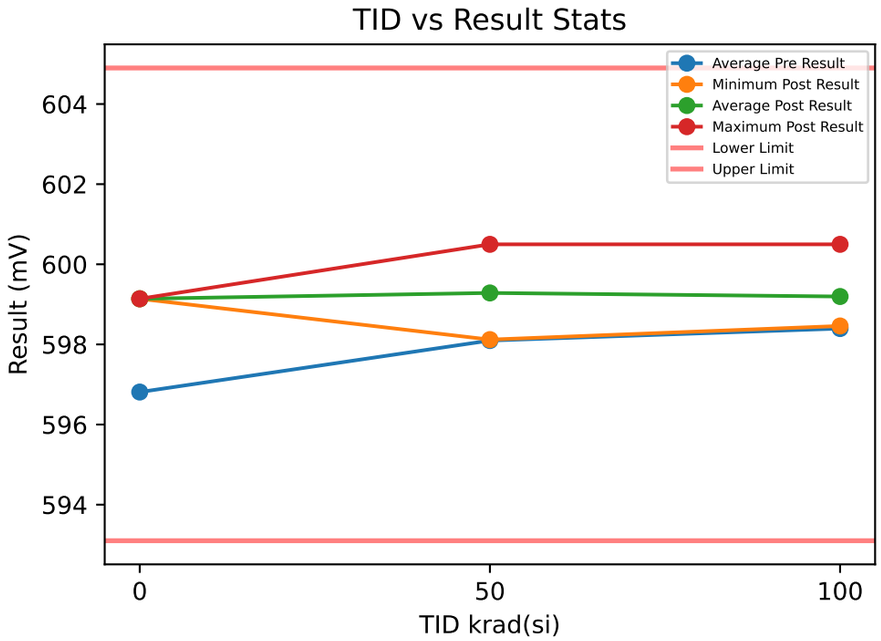
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

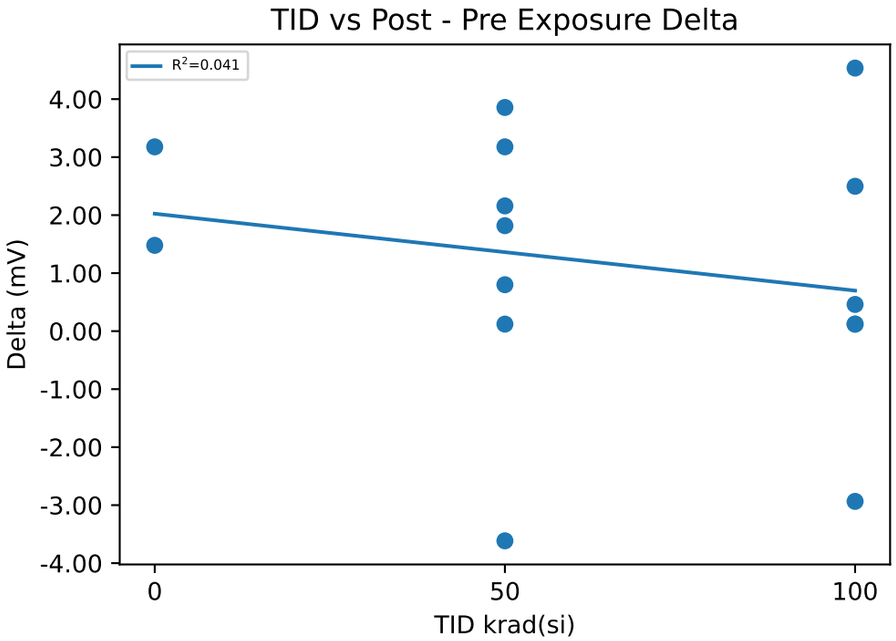
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	598.83	598.37	-0.464
89	50	Biased	600.87	599.73	-1.142
90	50	Biased	598.83	600.4	1.572
92	50	Biased	599.85	598.03	-1.822
93	50	Unbiased	599.17	598.37	-0.803
94	50	Unbiased	599.85	600.4	0.554
95	50	Unbiased	595.78	599.39	3.608
96	100	Biased	600.19	597.69	-2.5
97	100	Biased	595.1	598.71	3.607
98	100	Biased	596.46	599.39	2.929
99	100	Unbiased	600.19	598.37	-1.821
100	100	Unbiased	600.19	599.39	-0.803
101	100	Unbiased	600.19	597.35	-2.839
102	0	Correlation	599.51	598.71	-0.803
103	0	Correlation	599.17	600.07	0.894

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	599.17	599.34	599.51	0.23971	598.71	599.39	600.07	0.96025	-0.803	0.0455	0.894	1.2
50	595.78	599.03	600.87	1.6017	598.03	599.24	600.4	0.99633	-1.822	0.21471	3.608	1.8689
100	595.1	598.72	600.19	2.3176	597.35	598.48	599.39	0.84951	-2.839	-0.23783	3.607	2.8114

Device Test: 13.21 VTH_SENSE(VTH_SENSE3_RISING/SENSE3/1.6/14/0/0/0/@VTH_SENSE)





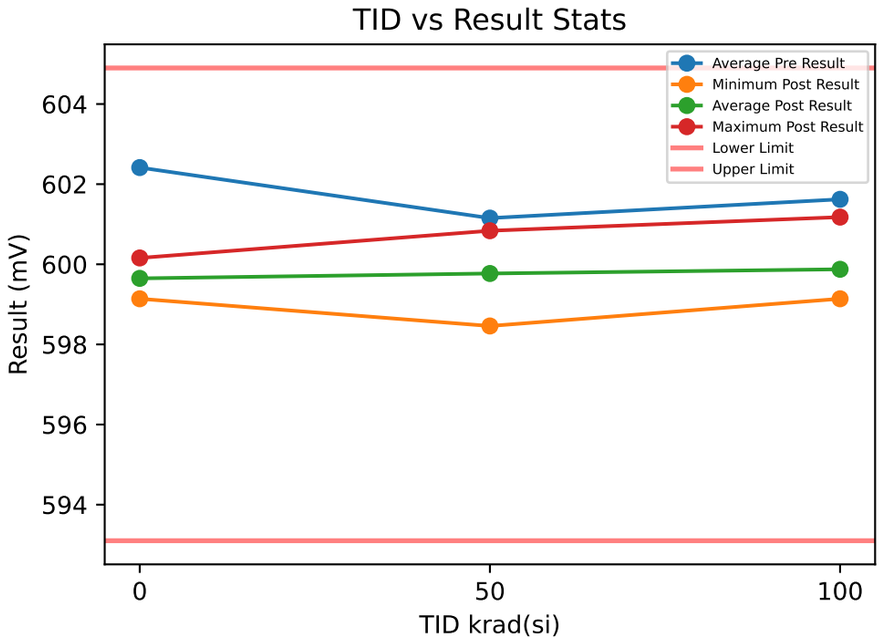
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

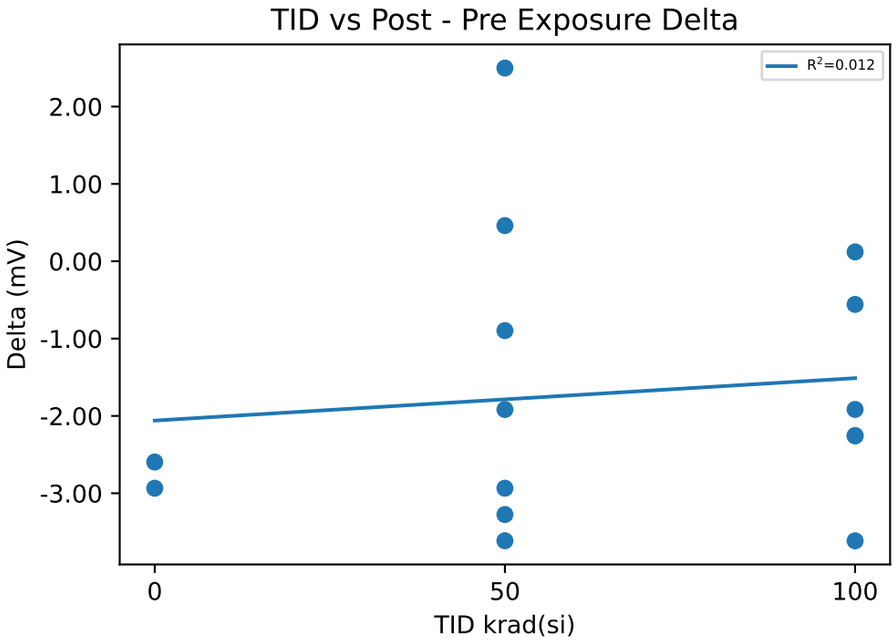
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	595.28	599.14	3.856
89	50	Biased	596.64	599.82	3.177
90	50	Biased	598.34	600.5	2.159
92	50	Biased	598.34	599.14	0.8
93	50	Unbiased	598.34	598.46	0.121
94	50	Unbiased	603.43	599.82	-3.615
95	50	Unbiased	596.3	598.12	1.818
96	100	Biased	596.3	598.8	2.497
97	100	Biased	598.68	599.14	0.46
98	100	Biased	600.38	600.5	0.121
99	100	Unbiased	602.07	599.14	-2.935
100	100	Unbiased	594.6	599.14	4.535
101	100	Unbiased	598.34	598.46	0.121
102	0	Correlation	597.66	599.14	1.479
103	0	Correlation	595.96	599.14	3.177

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	595.96	596.81	597.66	1.2007	599.14	599.14	599.14	0	1.479	2.328	3.177	1.2007
50	595.28	598.1	603.43	2.6429	598.12	599.28	600.5	0.82866	-3.615	1.188	3.856	2.4756
100	594.6	598.4	602.07	2.6944	598.46	599.2	600.5	0.69343	-2.935	0.79983	4.535	2.5226

Device Test: 13.22 VTH_SENSE(VTH_SENSE3_FALLING/SENSE3/1.6/14/0/0/0/@VTH_SENSE)





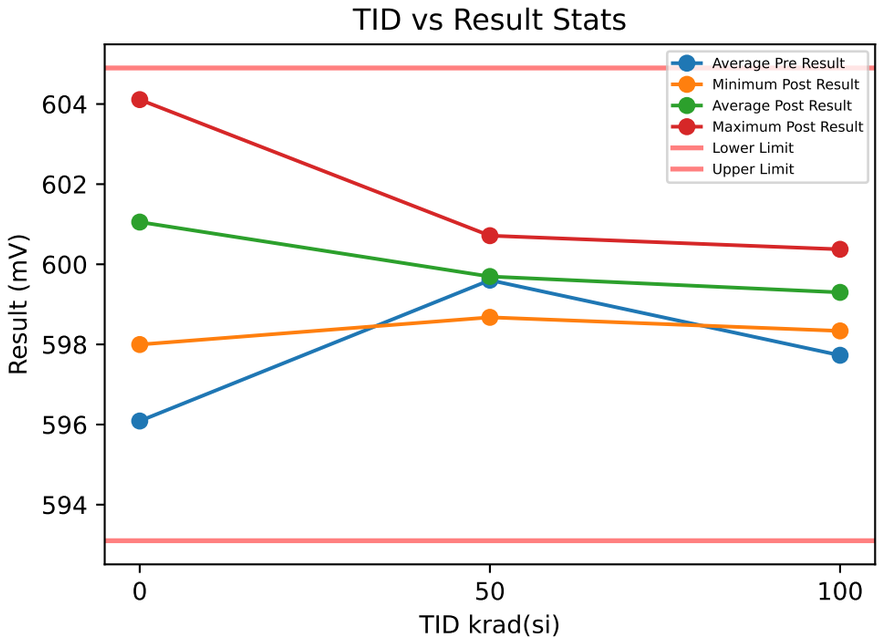
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

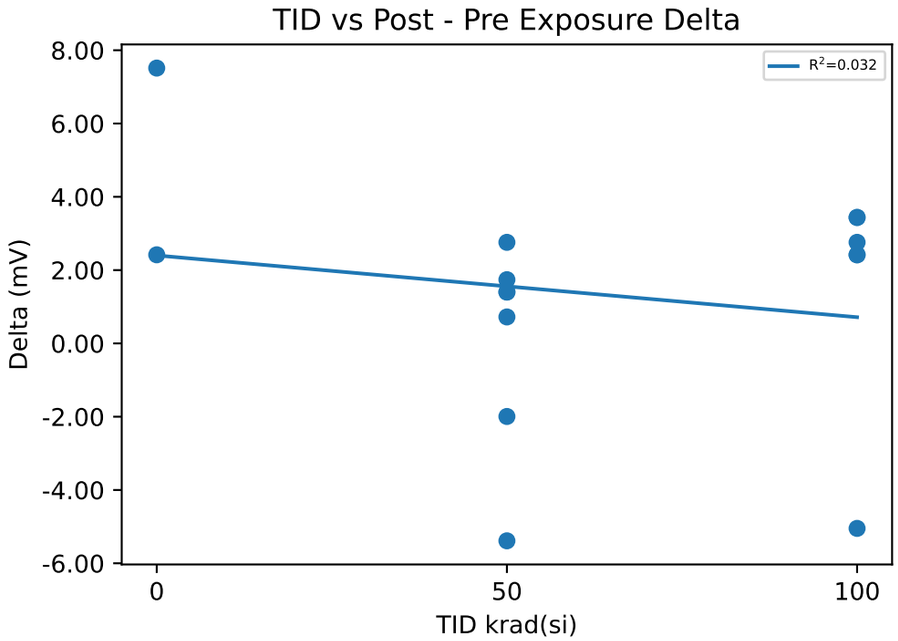
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	599.02	599.48	0.461
89	50	Biased	601.39	600.5	-0.897
90	50	Biased	602.75	600.84	-1.917
92	50	Biased	603.09	599.48	-3.614
93	50	Unbiased	601.74	598.46	-3.275
94	50	Unbiased	603.43	600.5	-2.935
95	50	Unbiased	596.64	599.14	2.498
96	100	Biased	600.04	600.16	0.121
97	100	Biased	602.75	599.14	-3.615
98	100	Biased	603.43	601.18	-2.256
99	100	Unbiased	602.07	599.82	-2.256
100	100	Unbiased	600.04	599.48	-0.558
101	100	Unbiased	601.39	599.48	-1.916
102	0	Correlation	601.74	599.14	-2.596
103	0	Correlation	603.09	600.16	-2.935

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	601.74	602.41	603.09	0.96025	599.14	599.65	600.16	0.72054	-2.935	-2.7655	-2.596	0.23971
50	596.64	601.15	603.43	2.4779	598.46	599.77	600.84	0.8643	-3.614	-1.3827	2.498	2.2342
100	600.04	601.62	603.43	1.403	599.14	599.88	601.18	0.72579	-3.615	-1.7467	0.121	1.3371

Device Test: 13.23 VTH_SENSE(VTH_SENSE4_RISING/SENSE4/1.6/14/0/0/0/@VTH_SENSE)





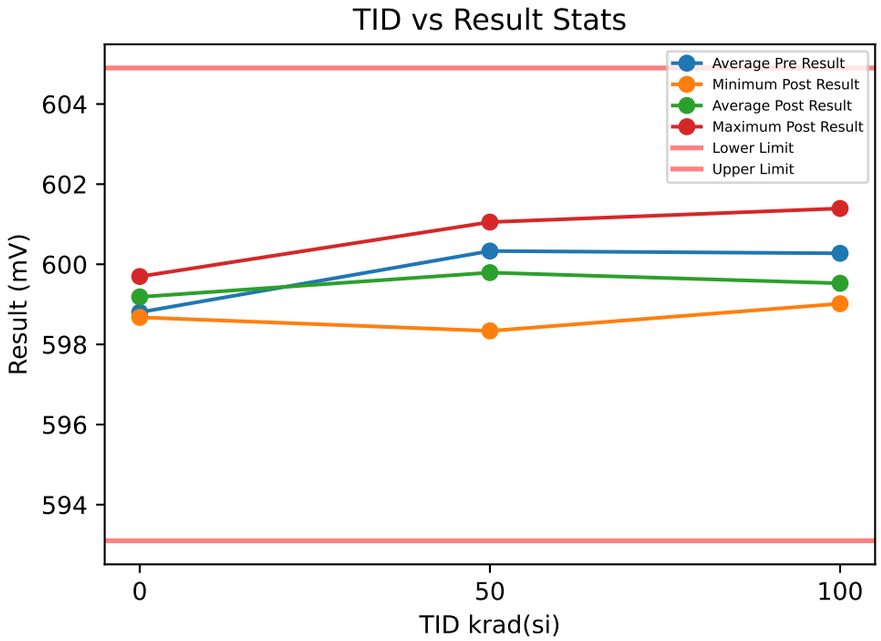
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

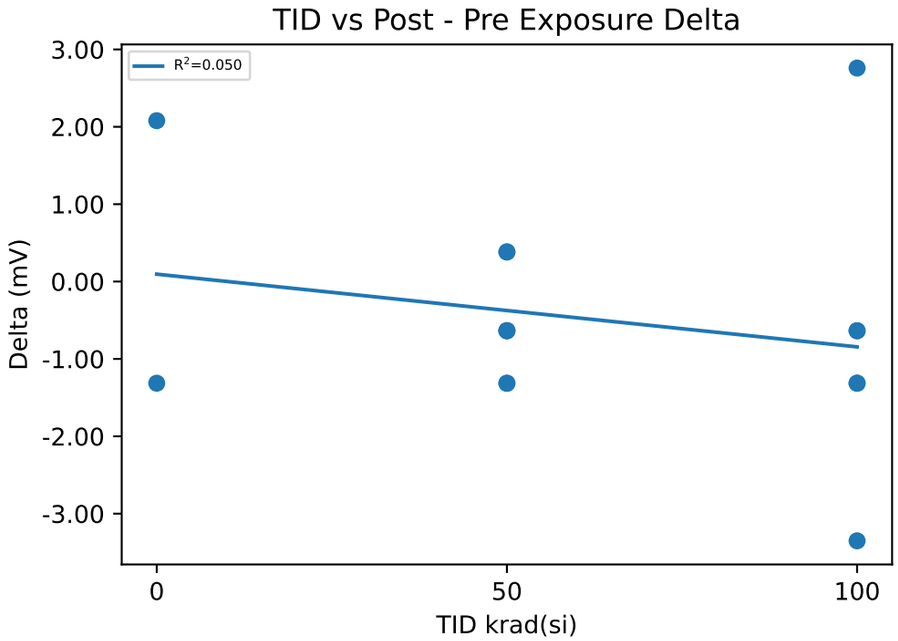
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	597.62	600.37	2.758
89	50	Biased	598.29	599.7	1.401
90	50	Biased	599.31	600.71	1.402
92	50	Biased	601.35	599.36	-1.994
93	50	Unbiased	596.94	598.68	1.739
94	50	Unbiased	599.65	600.37	0.722
95	50	Unbiased	604.06	598.68	-5.387
96	100	Biased	603.38	598.34	-5.048
97	100	Biased	596.94	599.36	2.418
98	100	Biased	596.94	600.37	3.437
99	100	Unbiased	596.26	598.68	2.418
100	100	Unbiased	596.6	599.36	2.758
101	100	Unbiased	596.26	599.7	3.437
102	0	Correlation	595.58	598	2.418
103	0	Correlation	596.6	604.11	7.513

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	595.58	596.09	596.6	0.71983	598	601.05	604.11	4.3225	2.418	4.9655	7.513	3.6027
50	596.94	599.6	604.06	2.4426	598.68	599.69	600.71	0.83194	-5.387	0.091571	2.758	2.8289
100	596.26	597.73	603.38	2.7876	598.34	599.3	600.37	0.72557	-5.048	1.57	3.437	3.2747

Device Test: 13.24 VTH_SENSE(VTH_SENSE4_FALLING/SENSE4/1.6/14/0/0/0/@VTH_SENSE)





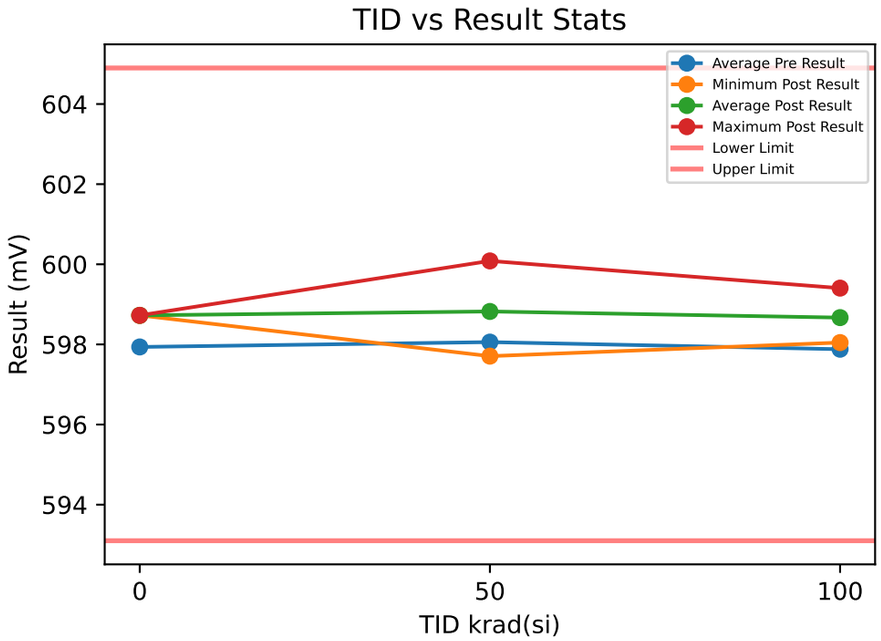
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

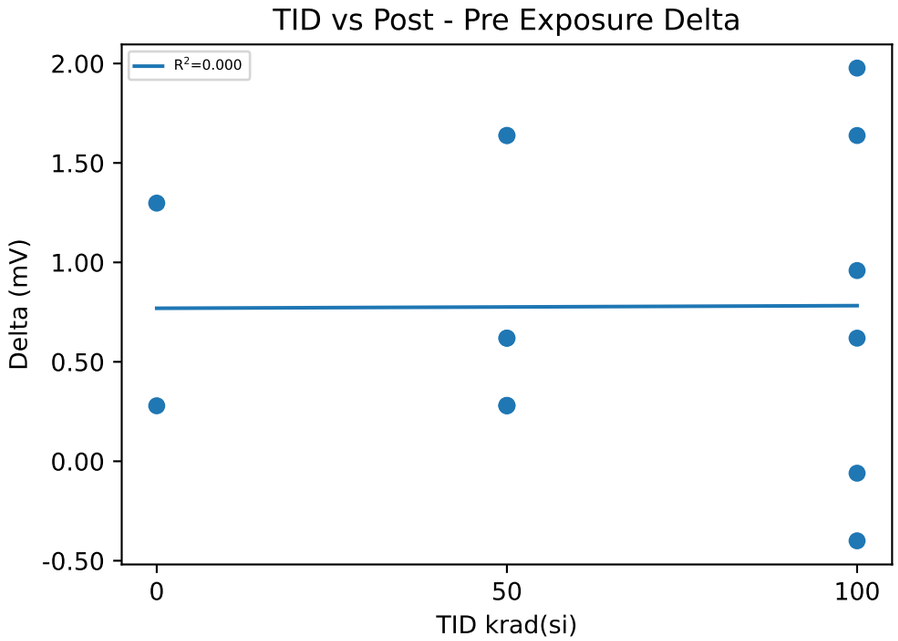
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	601.35	600.03	-1.314
89	50	Biased	601.01	600.37	-0.635
90	50	Biased	601.69	601.05	-0.635
92	50	Biased	598.63	599.02	0.382
93	50	Unbiased	598.97	598.34	-0.636
94	50	Unbiased	600.67	601.05	0.383
95	50	Unbiased	599.99	598.68	-1.315
96	100	Biased	599.65	599.02	-0.636
97	100	Biased	599.65	599.02	-0.636
98	100	Biased	598.63	601.39	2.759
99	100	Unbiased	600.33	599.02	-1.314
100	100	Unbiased	601.01	599.7	-1.314
101	100	Unbiased	602.37	599.02	-3.351
102	0	Correlation	596.6	598.68	2.079
103	0	Correlation	601.01	599.7	-1.314

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	596.6	598.8	601.01	3.1198	598.68	599.19	599.7	0.72054	-1.314	0.3825	2.079	2.3992
50	598.63	600.33	601.69	1.1756	598.34	599.79	601.05	1.1212	-1.315	-0.53857	0.383	0.69869
100	598.63	600.27	602.37	1.2952	599.02	599.53	601.39	0.95443	-3.351	-0.74867	2.759	1.987

Device Test: 13.25 VTH_SENSE(VTH_SENSE1_RISING/SENSE1/7/14/0/0/0/@VTH_SENSE)





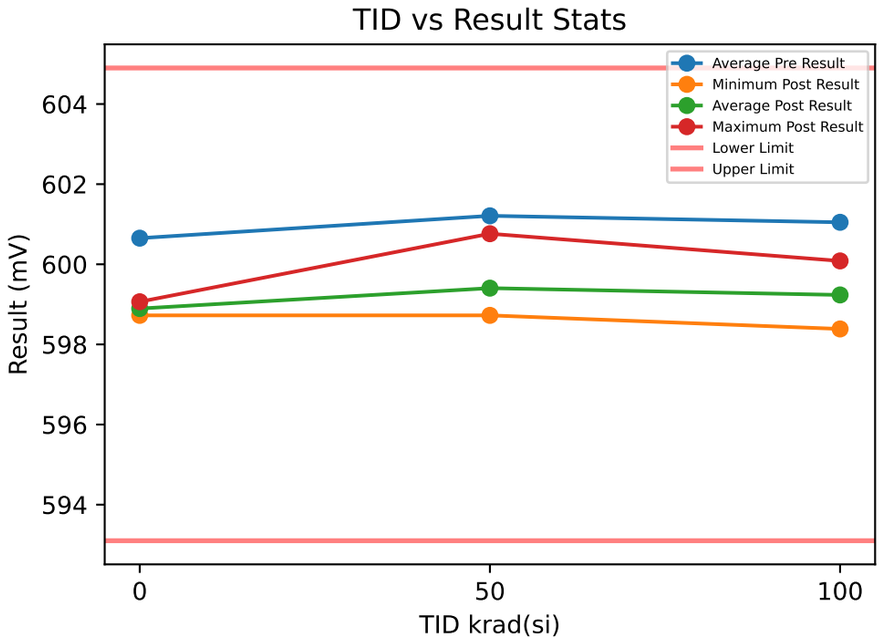
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

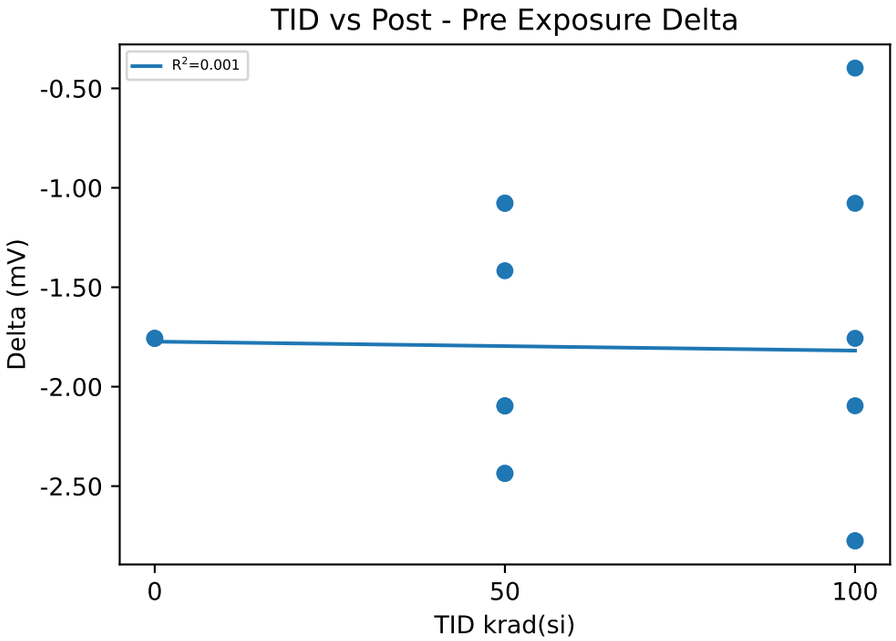
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	596.75	598.39	1.638
89	50	Biased	598.45	598.73	0.279
90	50	Biased	598.45	600.08	1.638
92	50	Biased	598.11	598.73	0.619
93	50	Unbiased	597.43	597.71	0.28
94	50	Unbiased	599.12	599.4	0.281
95	50	Unbiased	598.11	598.73	0.619
96	100	Biased	598.45	598.05	-0.4
97	100	Biased	597.43	598.05	0.619
98	100	Biased	598.45	599.4	0.959
99	100	Unbiased	597.09	599.07	1.977
100	100	Unbiased	597.43	599.07	1.638
101	100	Unbiased	598.45	598.39	-0.06
102	0	Correlation	597.43	598.73	1.298
103	0	Correlation	598.45	598.73	0.279

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	597.43	597.94	598.45	0.72054	598.73	598.73	598.73	0	0.279	0.7885	1.298	0.72054
50	596.75	598.06	599.12	0.76988	597.71	598.82	600.08	0.75212	0.279	0.76486	1.638	0.61544
100	597.09	597.88	598.45	0.63226	598.05	598.67	599.4	0.58509	-0.4	0.78883	1.977	0.93

Device Test: 13.26 VTH_SENSE(VTH_SENSE1_FALLING/SENSE1/7/14/0/0/0/@VTH_SENSE)





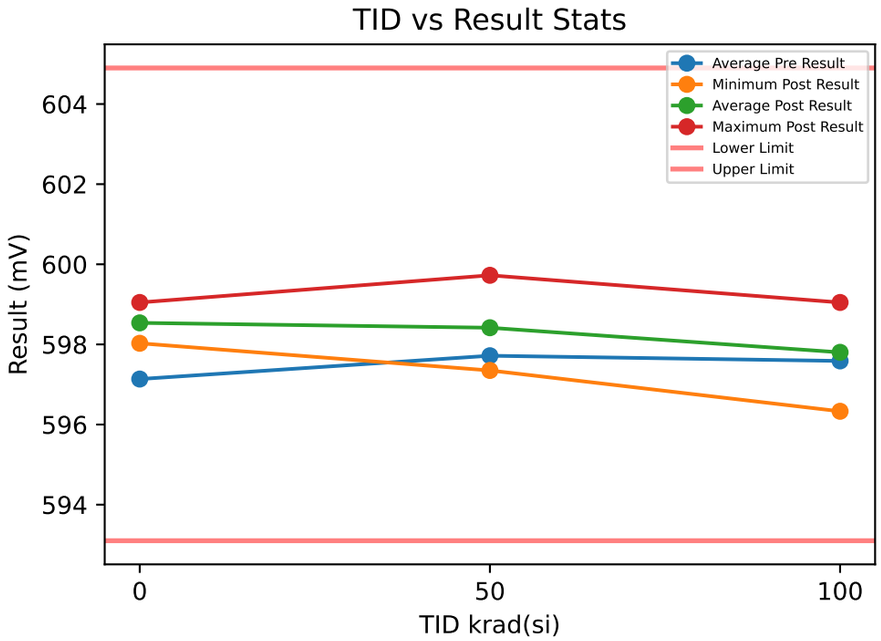
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

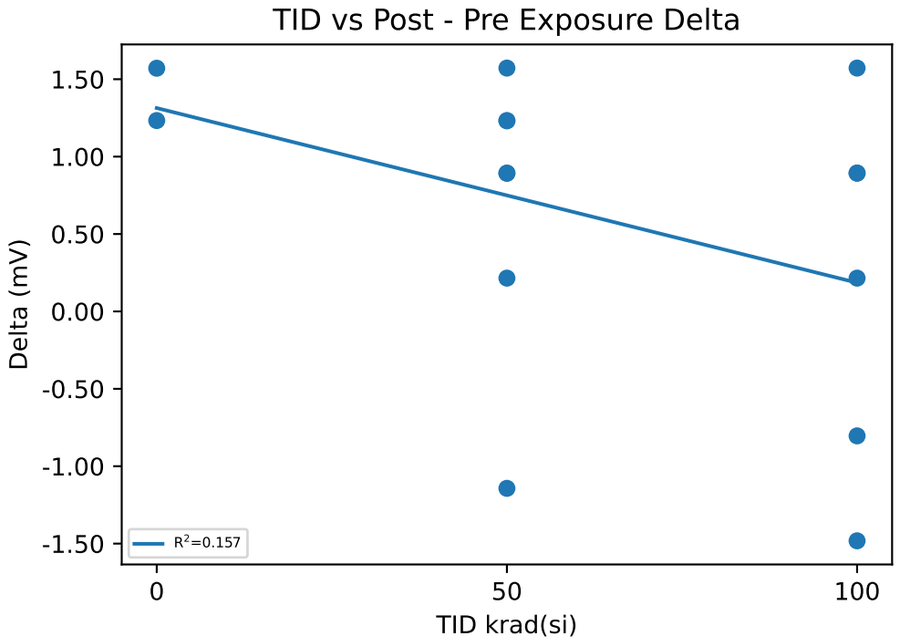
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	601.16	598.73	-2.436
89	50	Biased	601.16	598.73	-2.436
90	50	Biased	601.5	600.42	-1.078
92	50	Biased	601.16	599.07	-2.096
93	50	Unbiased	600.82	598.73	-2.097
94	50	Unbiased	601.84	600.76	-1.077
95	50	Unbiased	600.82	599.4	-1.417
96	100	Biased	601.16	598.39	-2.775
97	100	Biased	601.16	599.07	-2.096
98	100	Biased	601.5	599.74	-1.757
99	100	Unbiased	600.82	599.74	-1.078
100	100	Unbiased	600.48	600.08	-0.398
101	100	Unbiased	601.16	598.39	-2.775
102	0	Correlation	600.48	598.73	-1.757
103	0	Correlation	600.82	599.07	-1.757

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	600.48	600.65	600.82	0.24042	598.73	598.89	599.07	0.24042	-1.757	-1.757	-1.757	0
50	600.82	601.21	601.84	0.36283	598.73	599.4	600.76	0.85472	-2.436	-1.8053	-1.077	0.60212
100	600.48	601.05	601.5	0.3507	598.39	599.23	600.08	0.73613	-2.775	-1.8132	-0.398	0.94621

Device Test: 13.27 VTH_SENSE(VTH_SENSE2_RISING/SENSE2/7/14/0/0/0/@VTH_SENSE)





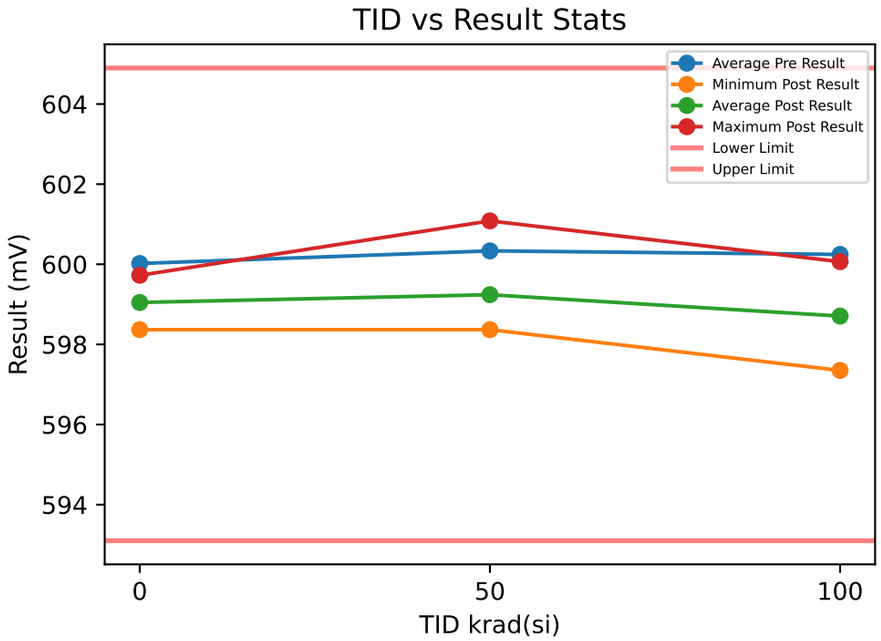
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

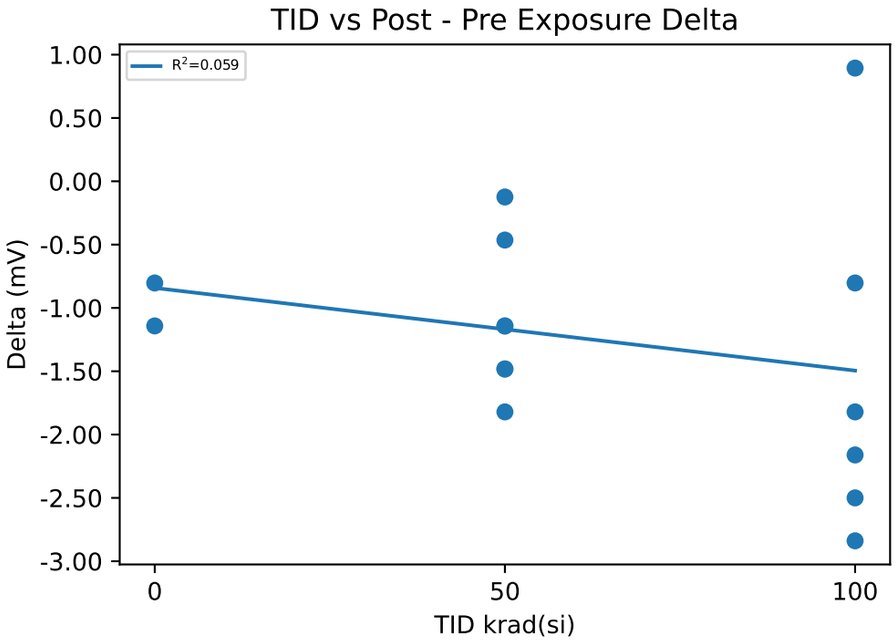
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	596.46	597.35	0.893
89	50	Biased	597.81	598.71	0.893
90	50	Biased	597.81	599.39	1.572
92	50	Biased	597.13	597.35	0.215
93	50	Unbiased	596.46	597.69	1.232
94	50	Unbiased	598.49	599.73	1.232
95	50	Unbiased	599.85	598.71	-1.143
96	100	Biased	597.13	597.35	0.215
97	100	Biased	598.83	597.35	-1.482
98	100	Biased	598.15	599.05	0.894
99	100	Unbiased	597.48	598.37	0.893
100	100	Unbiased	596.8	598.37	1.572
101	100	Unbiased	597.13	596.33	-0.804
102	0	Correlation	596.46	598.03	1.571
103	0	Correlation	597.81	599.05	1.233

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	596.46	597.14	597.81	0.95954	598.03	598.54	599.05	0.72054	1.233	1.402	1.571	0.239
50	596.46	597.72	599.85	1.2031	597.35	598.42	599.73	0.96824	-1.143	0.69914	1.572	0.91586
100	596.8	597.59	598.83	0.76383	596.33	597.8	599.05	0.97603	-1.482	0.21467	1.572	1.1559

Device Test: 13.28 VTH_SENSE(VTH_SENSE2_FALLING/SENSE2/7/14/0/0/0/@VTH_SENSE)





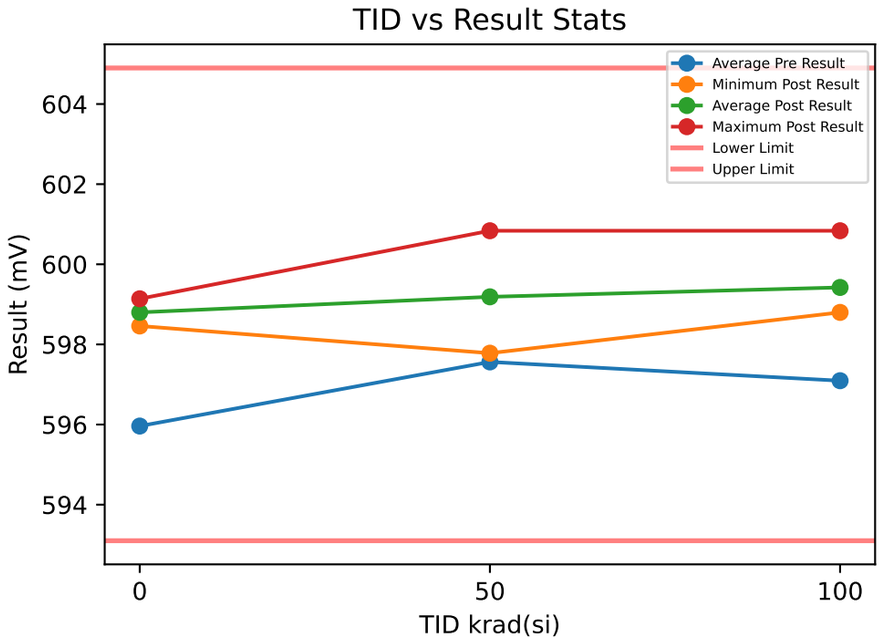
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

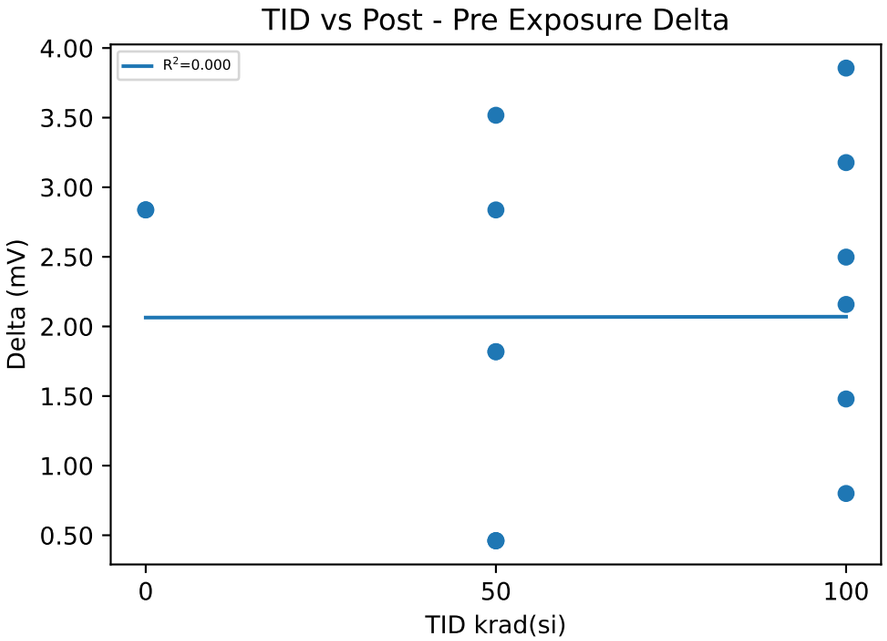
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	598.83	598.37	-0.464
89	50	Biased	600.87	599.73	-1.142
90	50	Biased	601.21	599.73	-1.482
92	50	Biased	600.19	598.37	-1.821
93	50	Unbiased	599.85	598.71	-1.143
94	50	Unbiased	601.21	601.08	-0.124
95	50	Unbiased	600.19	598.71	-1.482
96	100	Biased	600.53	597.69	-2.839
97	100	Biased	600.19	598.03	-2.161
98	100	Biased	601.55	599.73	-1.821
99	100	Unbiased	600.19	599.39	-0.803
100	100	Unbiased	599.17	600.07	0.894
101	100	Unbiased	599.85	597.35	-2.5
102	0	Correlation	599.51	598.37	-1.142
103	0	Correlation	600.53	599.73	-0.803

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	599.51	600.02	600.53	0.71983	598.37	599.05	599.73	0.95954	-1.142	-0.9725	-0.803	0.23971
50	598.83	600.33	601.21	0.85055	598.37	599.24	601.08	0.99633	-1.821	-1.094	-0.124	0.60168
100	599.17	600.25	601.55	0.78593	597.35	598.71	600.07	1.1559	-2.839	-1.5383	0.894	1.3814

Device Test: 13.29 VTH_SENSE(VTH_SENSE3_RISING/SENSE3/7/14/0/0/0/@VTH_SENSE)





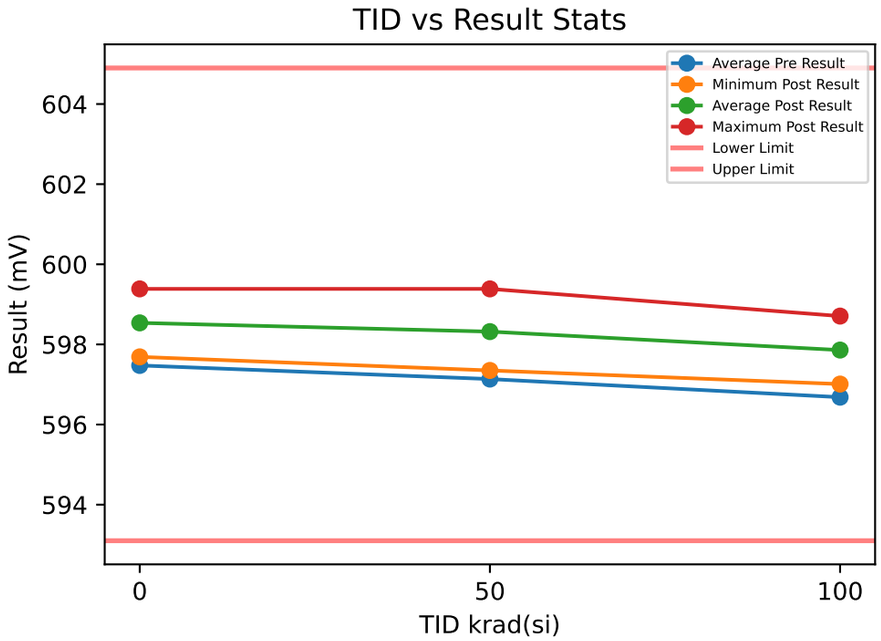
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

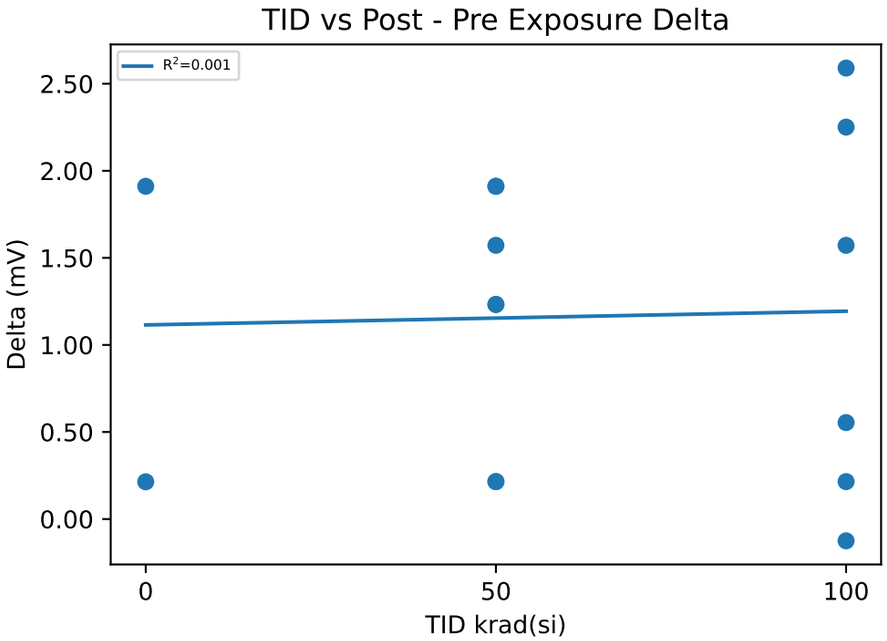
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	596.64	598.46	1.819
89	50	Biased	595.96	599.48	3.517
90	50	Biased	598	600.84	2.837
92	50	Biased	599.02	599.48	0.461
93	50	Unbiased	597.32	597.78	0.461
94	50	Unbiased	598	599.82	1.818
95	50	Unbiased	598	598.46	0.46
96	100	Biased	597.66	599.14	1.479
97	100	Biased	595.28	599.14	3.856
98	100	Biased	598.68	600.84	2.158
99	100	Unbiased	598.68	599.48	0.8
100	100	Unbiased	596.64	599.14	2.498
101	100	Unbiased	595.62	598.8	3.177
102	0	Correlation	595.62	598.46	2.838
103	0	Correlation	596.3	599.14	2.837

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	595.62	595.96	596.3	0.48083	598.46	598.8	599.14	0.48013	2.837	2.8375	2.838	0.00070711
50	595.96	597.56	599.02	1.0134	597.78	599.19	600.84	1.0267	0.46	1.6247	3.517	1.2376
100	595.28	597.09	598.68	1.483	598.8	599.42	600.84	0.72579	0.8	2.328	3.856	1.1108

Device Test: 13.3 VTH_SENSE(VTH_SENSE2_RISING/SENSE2/1.6/3/0/0/0/@VTH_SENSE)





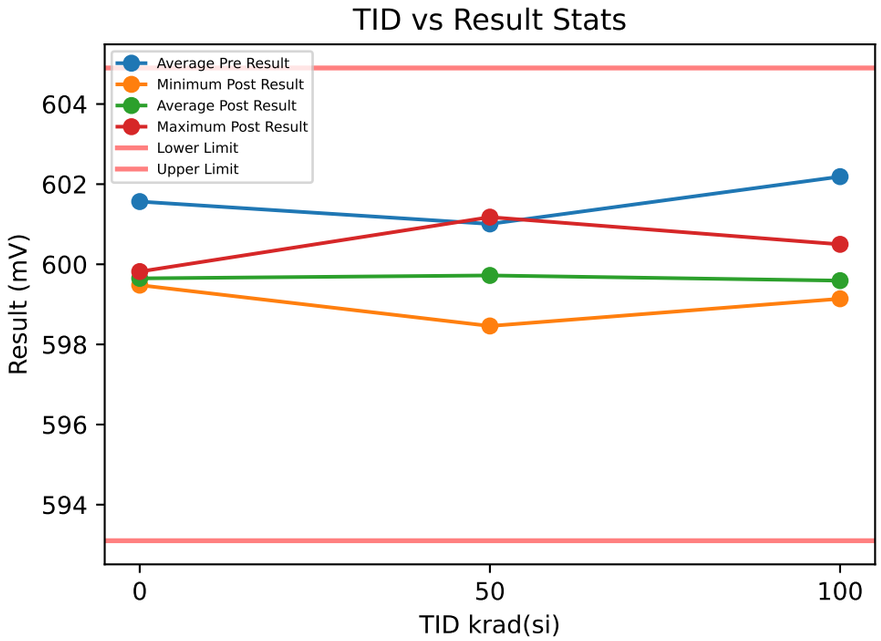
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

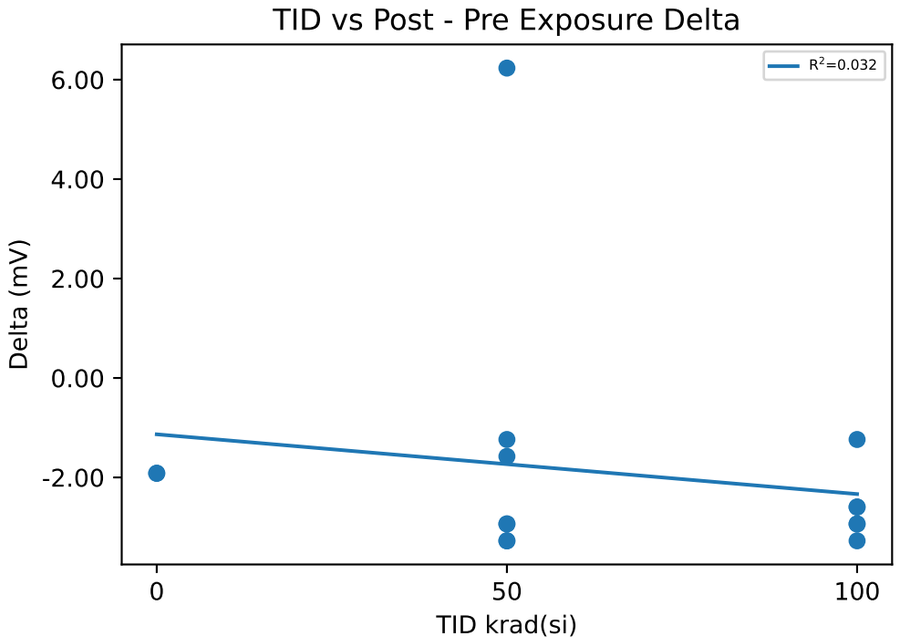
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	596.46	597.69	1.232
89	50	Biased	597.48	599.05	1.572
90	50	Biased	597.48	599.39	1.911
92	50	Biased	597.13	597.35	0.215
93	50	Unbiased	597.13	597.35	0.215
94	50	Unbiased	598.15	599.39	1.233
95	50	Unbiased	596.12	598.03	1.911
96	100	Biased	597.13	597.35	0.215
97	100	Biased	595.78	597.35	1.572
98	100	Biased	598.15	598.71	0.554
99	100	Unbiased	596.12	598.37	2.251
100	100	Unbiased	595.78	598.37	2.59
101	100	Unbiased	597.13	597.01	-0.125
102	0	Correlation	597.48	597.69	0.214
103	0	Correlation	597.48	599.39	1.911

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	597.48	597.48	597.48	0	597.69	598.54	599.39	1.2	0.214	1.0625	1.911	1.2
50	596.12	597.14	598.15	0.67867	597.35	598.32	599.39	0.92794	0.215	1.1841	1.911	0.71766
100	595.78	596.68	598.15	0.95162	597.01	597.86	598.71	0.70374	-0.125	1.1762	2.59	1.1238

Device Test: 13.30 VTH_SENSE(VTH_SENSE3_FALLING/SENSE3/7/14/0/0/0/@VTH_SENSE)





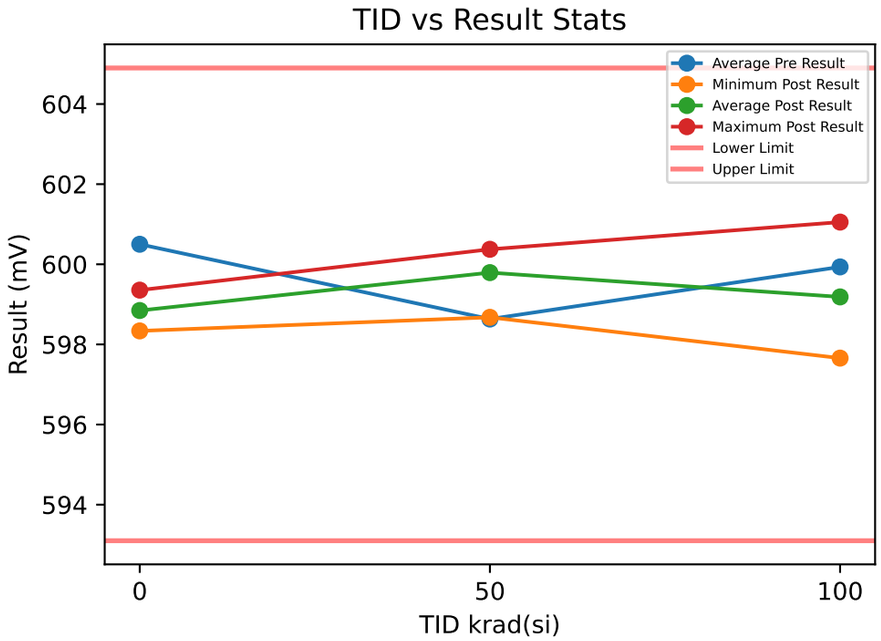
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

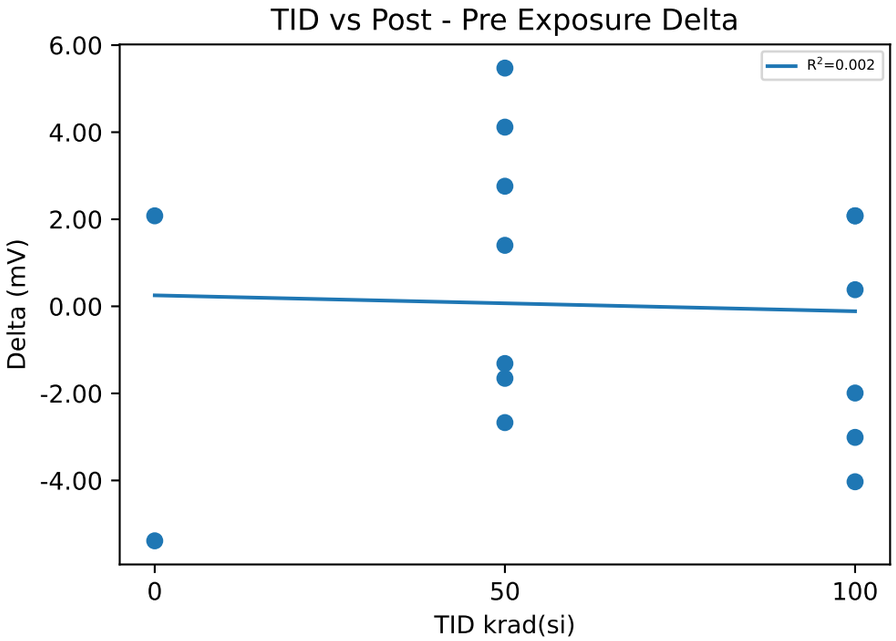
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	601.06	599.48	-1.577
89	50	Biased	593.92	600.16	6.233
90	50	Biased	602.41	601.18	-1.237
92	50	Biased	602.41	599.48	-2.935
93	50	Unbiased	601.74	598.46	-3.275
94	50	Unbiased	603.09	600.16	-2.935
95	50	Unbiased	602.41	599.14	-3.275
96	100	Biased	602.75	599.82	-2.936
97	100	Biased	602.07	599.48	-2.595
98	100	Biased	602.75	599.48	-3.275
99	100	Unbiased	601.74	600.5	-1.237
100	100	Unbiased	602.07	599.14	-2.935
101	100	Unbiased	601.74	599.14	-2.596
102	0	Correlation	601.39	599.48	-1.916
103	0	Correlation	601.74	599.82	-1.917

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	601.39	601.57	601.74	0.24042	599.48	599.65	599.82	0.23971	-1.917	-1.9165	-1.916	0.00070711
50	593.92	601.01	603.09	3.1879	598.46	599.72	601.18	0.87062	-3.275	-1.2859	6.233	3.415
100	601.74	602.19	602.75	0.46414	599.14	599.59	600.5	0.51144	-3.275	-2.5957	-1.237	0.71252

Device Test: 13.31 VTH_SENSE(VTH_SENSE4_RISING/SENSE4/7/14/0/0/0/@VTH_SENSE)





Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

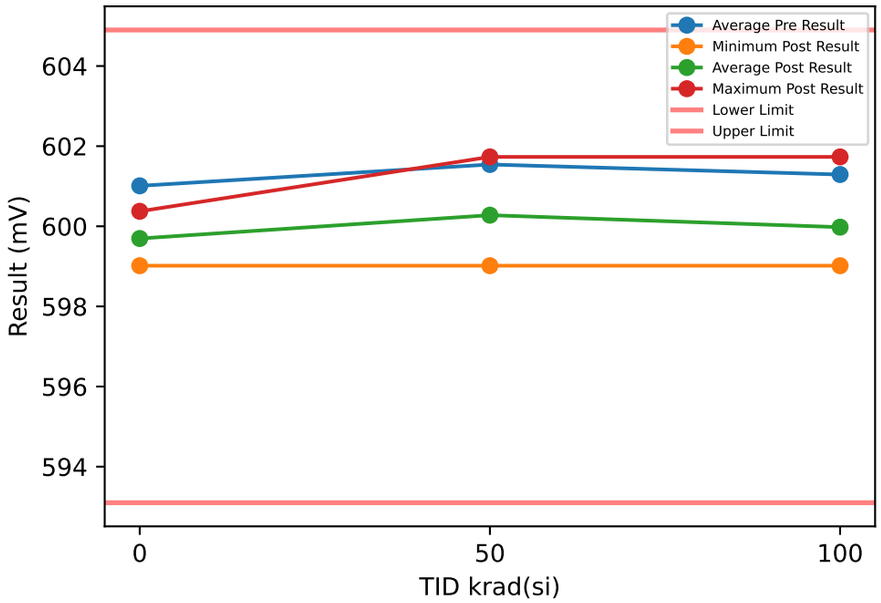
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	597.28	600.03	2.759
89	50	Biased	595.58	599.7	4.116
90	50	Biased	603.04	600.37	-2.671
92	50	Biased	600.33	598.68	-1.654
93	50	Unbiased	594.9	600.37	5.473
94	50	Unbiased	598.97	600.37	1.401
95	50	Unbiased	600.33	599.02	-1.314
96	100	Biased	596.26	598.34	2.079
97	100	Biased	598.63	599.02	0.382
98	100	Biased	603.04	601.05	-1.992
99	100	Unbiased	595.58	597.66	2.079
100	100	Unbiased	602.71	599.7	-3.011
101	100	Unbiased	603.38	599.36	-4.03
102	0	Correlation	603.72	598.34	-5.387
103	0	Correlation	597.28	599.36	2.079

Test Statistics (mV)

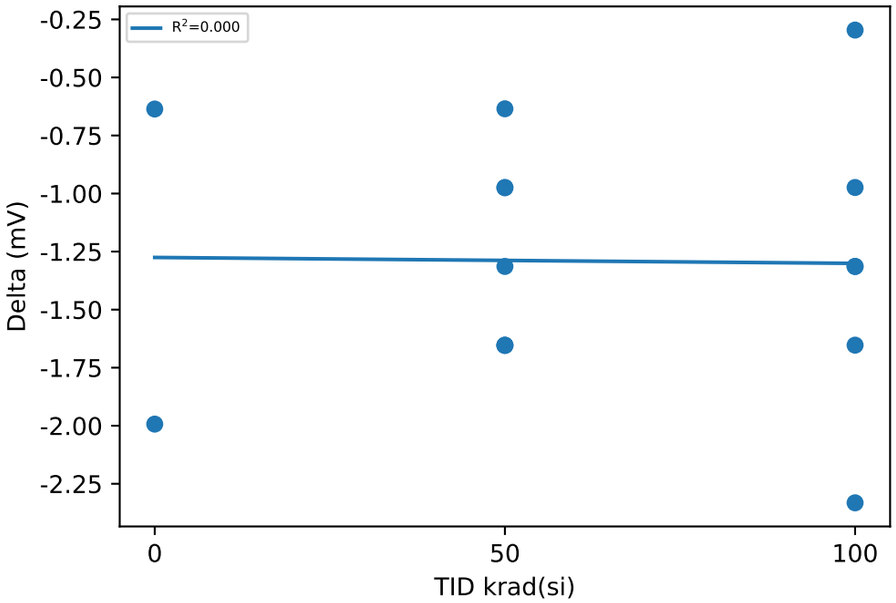
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	597.28	600.5	603.72	4.5594	598.34	598.85	599.36	0.71983	-5.387	-1.654	2.079	5.2793
50	594.9	598.63	603.04	2.8993	598.68	599.79	600.37	0.69908	-2.671	1.1586	5.473	3.127
100	595.58	599.93	603.38	3.562	597.66	599.19	601.05	1.1711	-4.03	-0.74883	2.079	2.6344

Device Test: 13.32 VTH_SENSE(VTH_SENSE4_FALLING/SENSE4/7/14/0/0/0/@VTH_SENSE)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



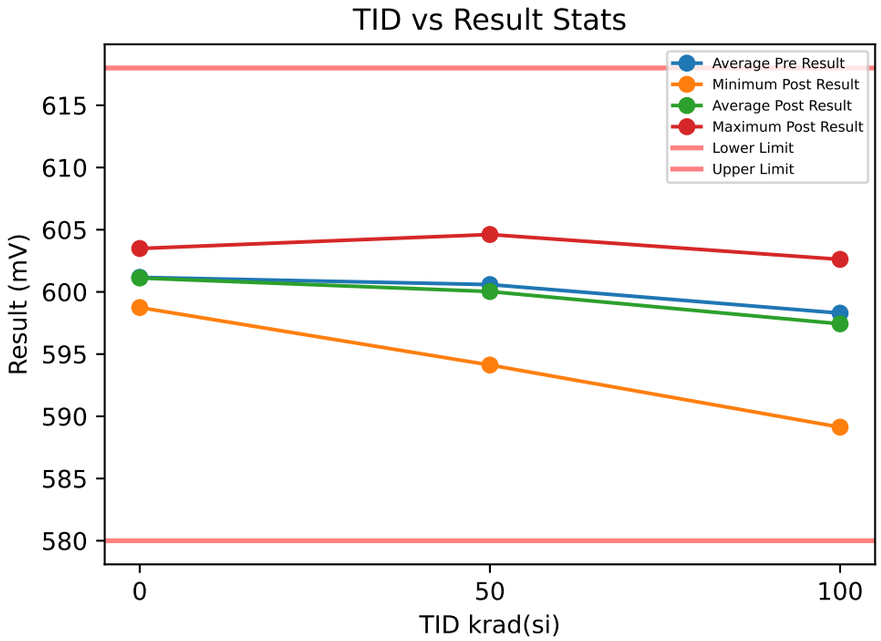
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

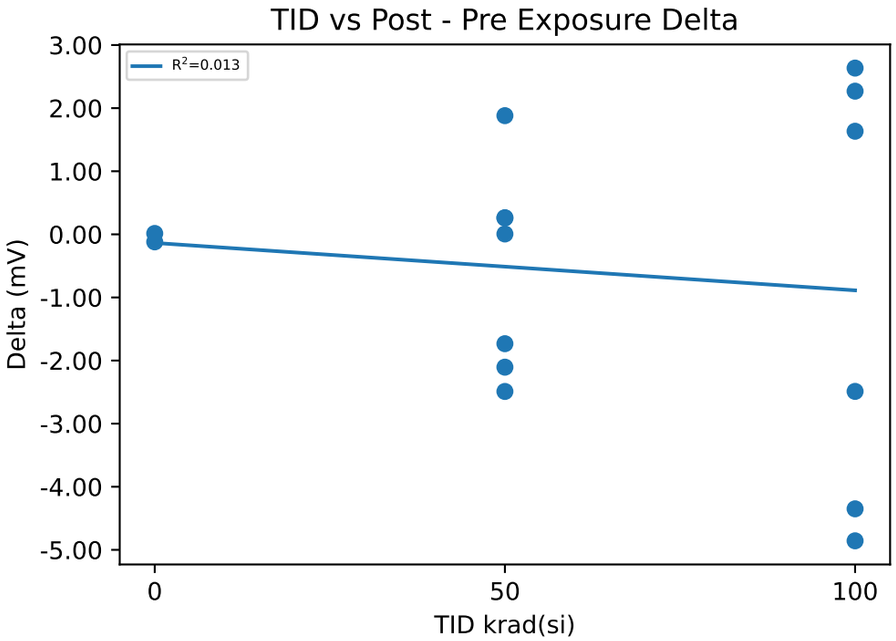
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	601.35	600.71	-0.635
89	50	Biased	602.03	600.37	-1.653
90	50	Biased	602.37	601.05	-1.314
92	50	Biased	601.01	599.36	-1.654
93	50	Unbiased	599.99	599.02	-0.975
94	50	Unbiased	602.71	601.73	-0.974
95	50	Unbiased	601.35	599.7	-1.654
96	100	Biased	599.99	599.7	-0.296
97	100	Biased	602.03	599.7	-2.332
98	100	Biased	603.38	601.73	-1.653
99	100	Unbiased	600.33	599.02	-1.314
100	100	Unbiased	601.01	600.03	-0.974
101	100	Unbiased	601.01	599.7	-1.314
102	0	Correlation	599.65	599.02	-0.636
103	0	Correlation	602.37	600.37	-1.993

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	599.65	601.01	602.37	1.9198	599.02	599.69	600.37	0.96025	-1.993	-1.3145	-0.636	0.95954
50	599.99	601.54	602.71	0.91605	599.02	600.28	601.73	0.97455	-1.654	-1.2656	-0.635	0.41257
100	599.99	601.29	603.38	1.2409	599.02	599.98	601.73	0.92146	-2.332	-1.3138	-0.296	0.6787

Device Test: 13.33 VTH_SR_UVLO_RISE(VTH_SR_UVLOB_RISING/SR_UVLOB/1.6/3/0/0/0/@VTH_SR_UVLO_RISE)





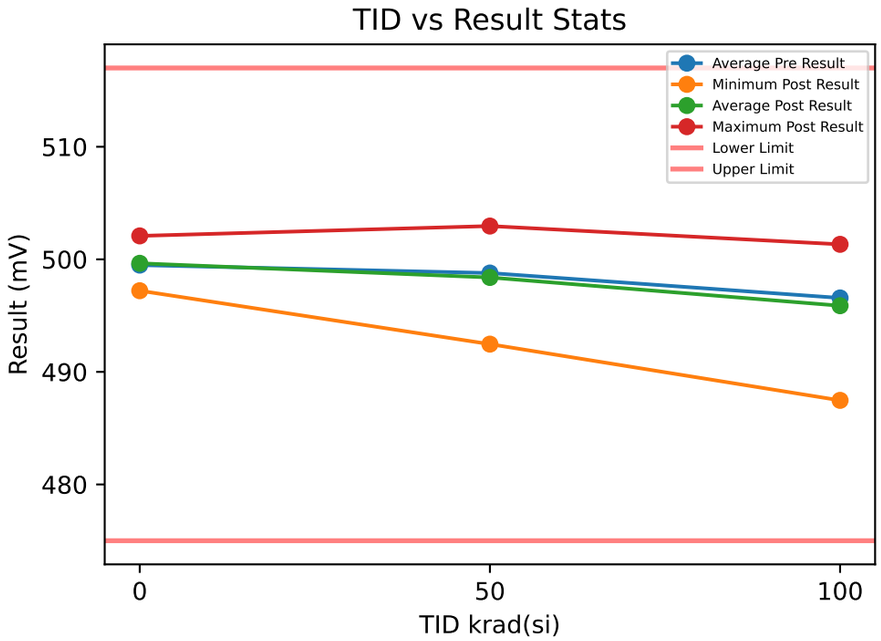
Test Results (Lower Limit = 580.0, Upper Limit = 618.0 (mV))

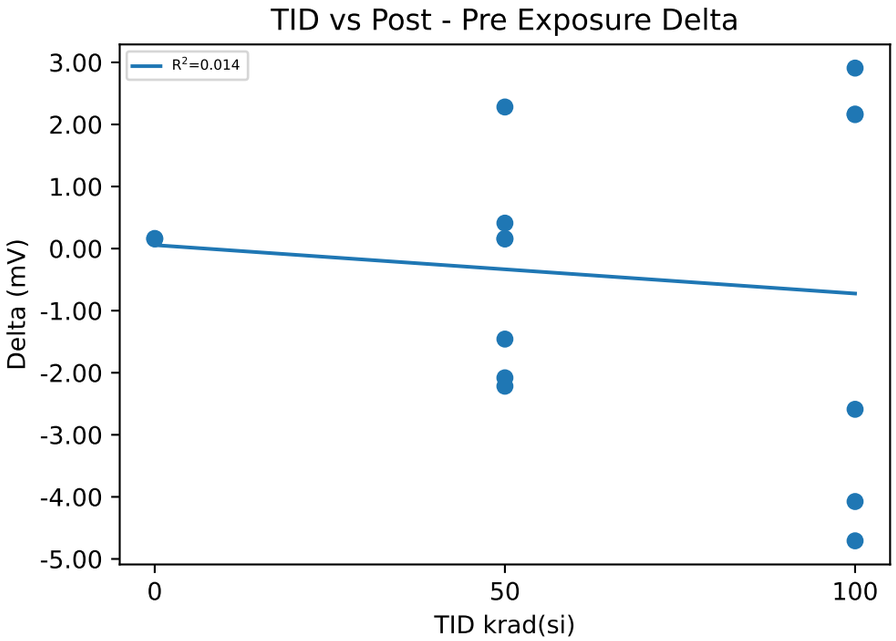
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	599.48	599.74	0.263
89	50	Biased	596.23	594.12	-2.105
90	50	Biased	604.23	604.24	0.006
92	50	Biased	603.23	600.74	-2.49
93	50	Unbiased	600.98	601.24	0.26
94	50	Unbiased	602.73	604.61	1.881
95	50	Unbiased	597.23	595.5	-1.733
96	100	Biased	601.86	599.37	-2.489
97	100	Biased	599.23	594.37	-4.857
98	100	Biased	593.48	589.13	-4.35
99	100	Unbiased	594.35	596.62	2.269
100	100	Unbiased	599.86	602.49	2.635
101	100	Unbiased	600.98	602.62	1.634
102	0	Correlation	603.61	603.49	-0.119
103	0	Correlation	598.73	598.75	0.014

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.73	601.17	603.61	3.4493	598.75	601.12	603.49	3.3552	-0.119	-0.0525	0.014	0.094045
50	596.23	600.59	604.23	3.07	594.12	600.03	604.61	4.0047	-2.49	-0.55971	1.881	1.5873
100	593.48	598.29	601.86	3.5205	589.13	597.43	602.62	5.1997	-4.857	-0.85967	2.635	3.4361

Device Test: 13.34 VTH_SR_UVLO_FALL(VTH_SR_UVLOB_FALLING/SR_UVLOB/1.6/3/0/0/0/@VTH_SR_UVLO_FALL)





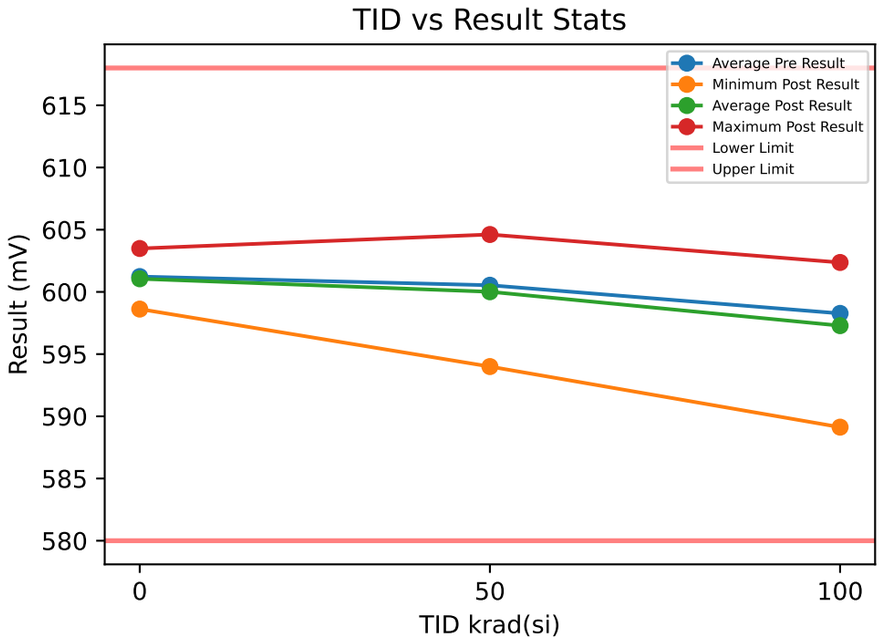
Test Results (Lower Limit = 475.0, Upper Limit = 517.0 (mV))

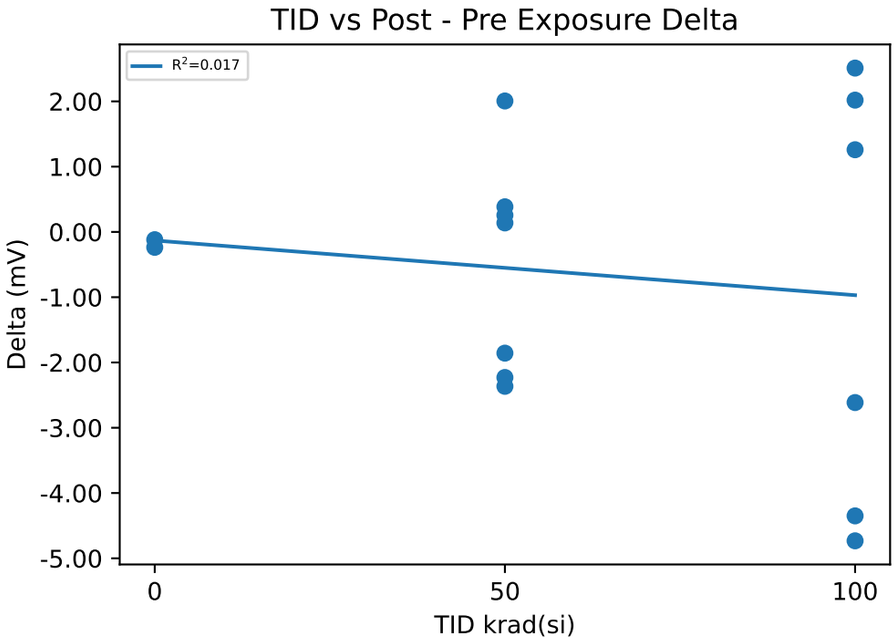
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	498.05	498.21	0.161
89	50	Biased	494.55	492.46	-2.082
90	50	Biased	502.55	502.71	0.155
92	50	Biased	501.43	499.21	-2.217
93	50	Unbiased	498.92	499.33	0.41
94	50	Unbiased	500.68	502.96	2.281
95	50	Unbiased	495.3	493.84	-1.458
96	100	Biased	500.3	497.71	-2.589
97	100	Biased	497.42	492.71	-4.708
98	100	Biased	491.55	487.47	-4.075
99	100	Unbiased	492.8	494.96	2.167
100	100	Unbiased	498.42	501.33	2.908
101	100	Unbiased	498.92	501.08	2.158
102	0	Correlation	501.93	502.08	0.156
103	0	Correlation	497.05	497.21	0.163

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	497.05	499.49	501.93	3.4493	497.21	499.65	502.08	3.4443	0.156	0.1595	0.163	0.0049497
50	494.55	498.78	502.55	3.0391	492.46	498.39	502.96	4.0185	-2.217	-0.39286	2.281	1.6184
100	491.55	496.57	500.3	3.5528	487.47	495.88	501.33	5.324	-4.708	-0.68983	2.908	3.4764

Device Test: 13.36 VTH_SR_UVLO_RISE(VTH_SR_UVLOB_RISING/SR_UVLOB/7/3/0/0/0/@VTH_SR_UVLO_RISE)





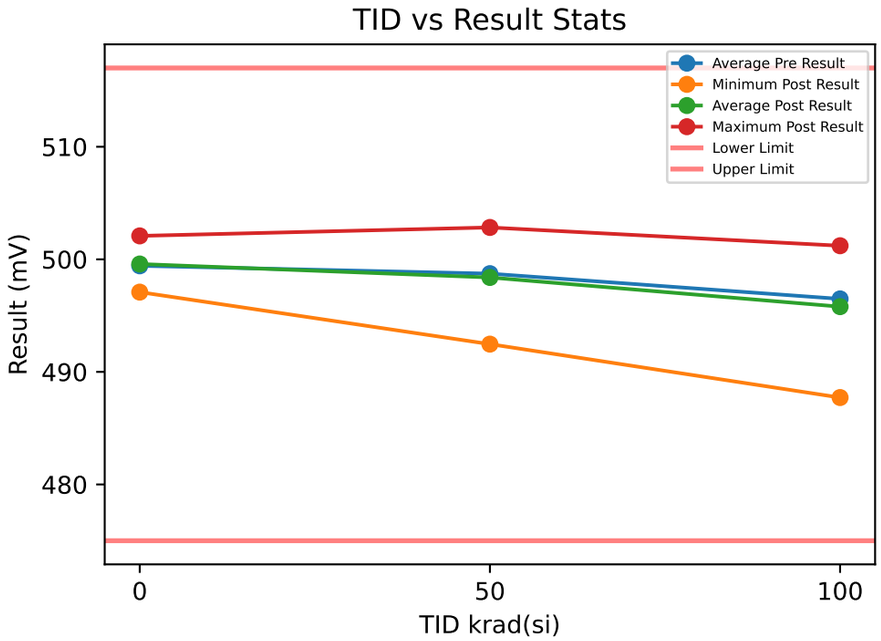
Test Results (Lower Limit = 580.0, Upper Limit = 618.0 (mV))

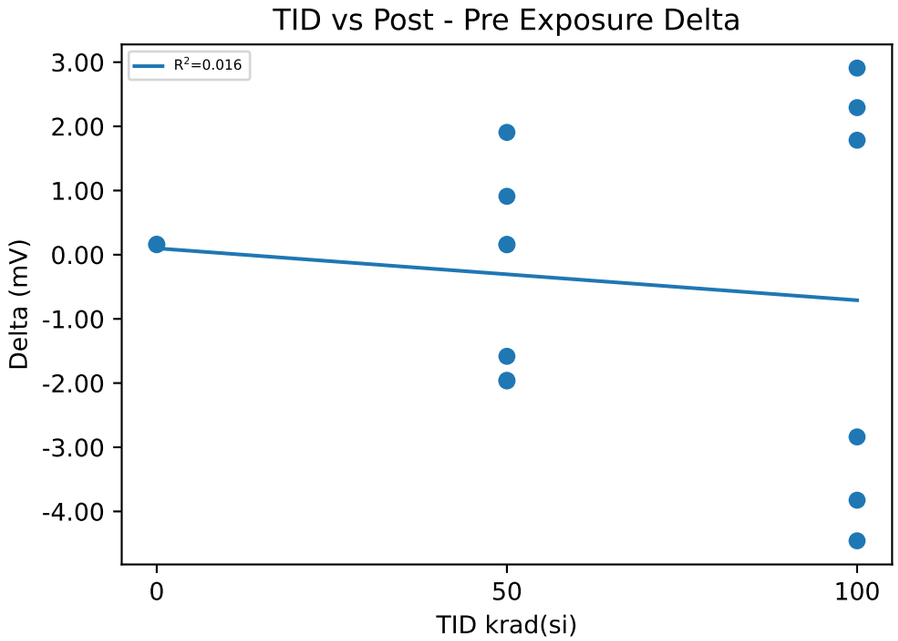
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	599.61	599.74	0.138
89	50	Biased	596.23	594	-2.23
90	50	Biased	604.11	604.37	0.256
92	50	Biased	603.11	600.74	-2.365
93	50	Unbiased	600.98	601.37	0.385
94	50	Unbiased	602.61	604.61	2.006
95	50	Unbiased	597.11	595.25	-1.857
96	100	Biased	601.98	599.37	-2.614
97	100	Biased	598.98	594.25	-4.732
98	100	Biased	593.48	589.13	-4.35
99	100	Unbiased	594.35	596.37	2.019
100	100	Unbiased	599.86	602.37	2.51
101	100	Unbiased	600.98	602.24	1.259
102	0	Correlation	603.61	603.49	-0.119
103	0	Correlation	598.86	598.62	-0.236

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.86	601.23	603.61	3.3609	598.62	601.06	603.49	3.4436	-0.236	-0.1775	-0.119	0.082731
50	596.23	600.54	604.11	3.0293	594	600.01	604.61	4.1114	-2.365	-0.52386	2.006	1.6508
100	593.48	598.27	601.98	3.5346	589.13	597.29	602.37	5.1246	-4.732	-0.98467	2.51	3.2952

Device Test: 13.37 VTH_SR_UVLO_FALL(VTH_SR_UVLOB_FALLING/SR_UVLOB/7/3/0/0/0/@VTH_SR_UVLO_FALL)





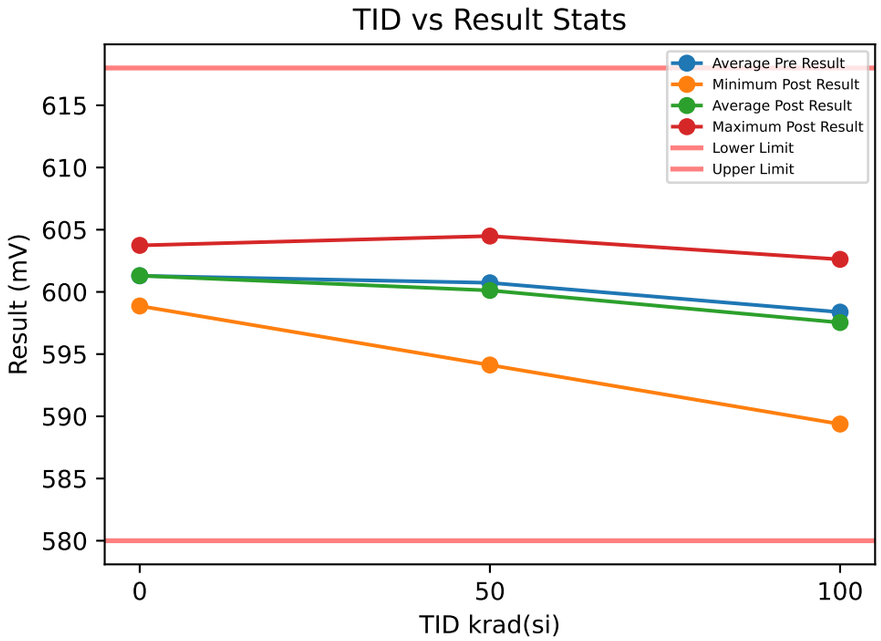
Test Results (Lower Limit = 475.0, Upper Limit = 517.0 (mV))

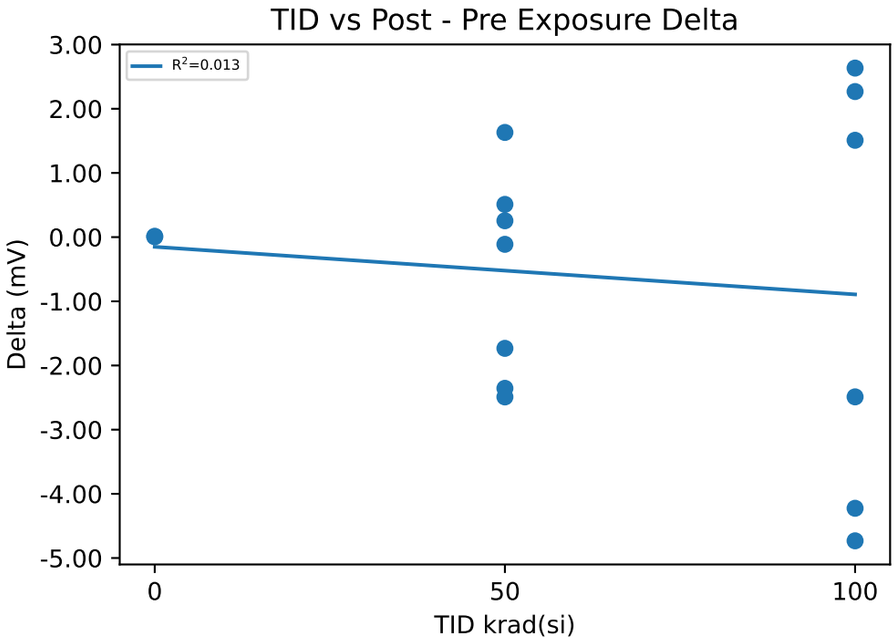
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	498.05	498.21	0.161
89	50	Biased	494.42	492.46	-1.957
90	50	Biased	502.68	502.83	0.155
92	50	Biased	501.3	499.33	-1.967
93	50	Unbiased	498.67	499.58	0.91
94	50	Unbiased	500.68	502.58	1.906
95	50	Unbiased	495.3	493.71	-1.583
96	100	Biased	500.43	497.59	-2.839
97	100	Biased	497.17	492.71	-4.458
98	100	Biased	491.55	487.72	-3.825
99	100	Unbiased	492.42	494.71	2.292
100	100	Unbiased	498.3	501.21	2.908
101	100	Unbiased	499.05	500.83	1.784
102	0	Correlation	501.93	502.08	0.156
103	0	Correlation	496.92	497.09	0.163

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	496.92	499.42	501.93	3.5377	497.09	499.58	502.08	3.5327	0.156	0.1595	0.163	0.0049497
50	494.42	498.73	502.68	3.0761	492.46	498.39	502.83	4.0126	-1.967	-0.33929	1.906	1.5226
100	491.55	496.49	500.43	3.6546	487.72	495.8	501.21	5.1719	-4.458	-0.68967	2.908	3.3646

Device Test: 13.39 VTH_SR_UVLO_RISE(VTH_SR_UVLOB_RISING/SR_UVLOB/1.6/14/0/0/0/@VTH_SR_UVLO_RISE)





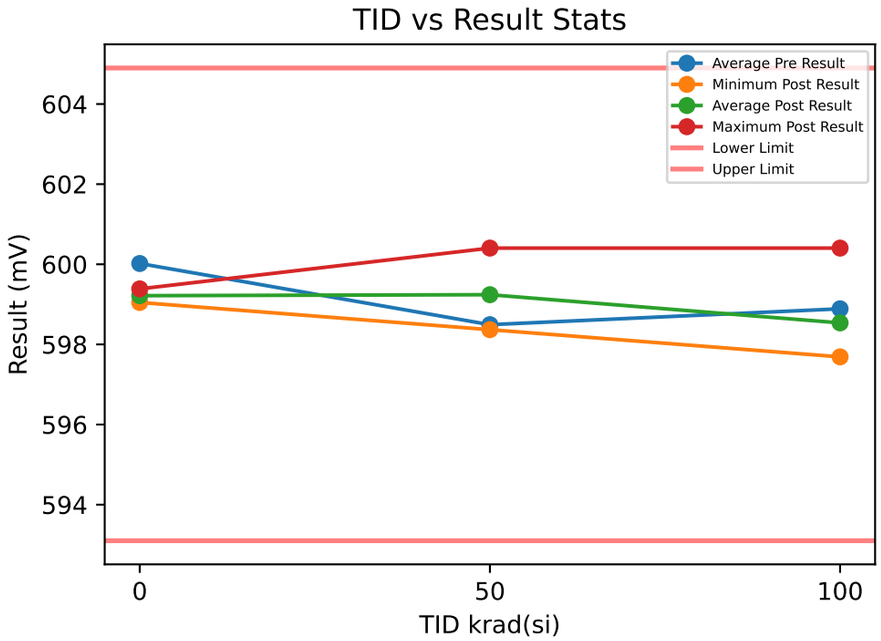
Test Results (Lower Limit = 580.0, Upper Limit = 618.0 (mV))

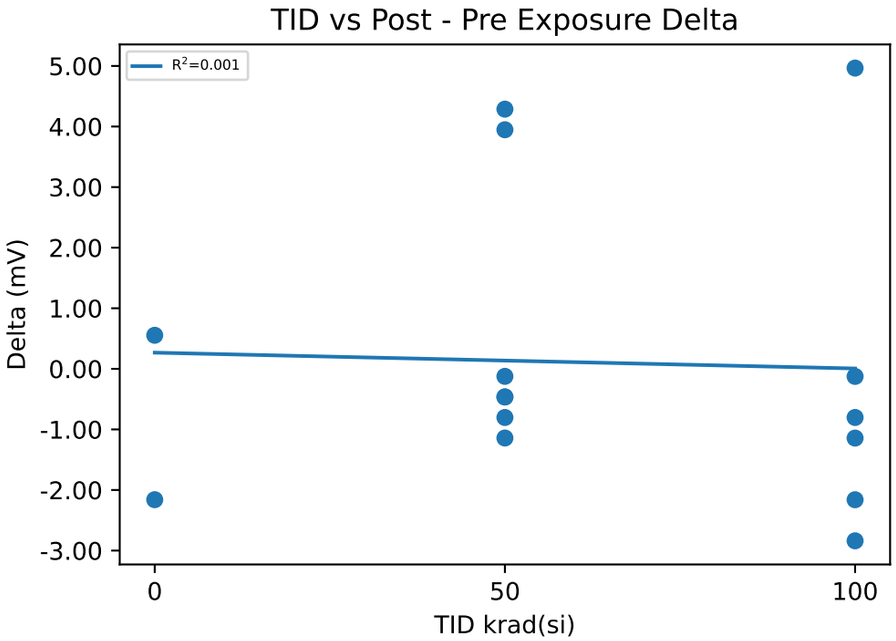
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	599.86	599.74	-0.112
89	50	Biased	596.48	594.12	-2.356
90	50	Biased	604.23	604.49	0.255
92	50	Biased	603.23	600.74	-2.49
93	50	Unbiased	601.11	601.62	0.51
94	50	Unbiased	602.86	604.49	1.631
95	50	Unbiased	597.36	595.62	-1.733
96	100	Biased	602.11	599.62	-2.489
97	100	Biased	599.11	594.37	-4.732
98	100	Biased	593.6	589.38	-4.225
99	100	Unbiased	594.48	596.75	2.268
100	100	Unbiased	599.98	602.62	2.634
101	100	Unbiased	600.98	602.49	1.509
102	0	Correlation	603.73	603.74	0.006
103	0	Correlation	598.86	598.87	0.013

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.86	601.3	603.73	3.4493	598.87	601.3	603.74	3.4443	0.006	0.0095	0.013	0.0049497
50	596.48	600.73	604.23	2.9841	594.12	600.12	604.49	4.0235	-2.49	-0.61357	1.631	1.5873
100	593.6	598.38	602.11	3.5159	589.38	597.54	602.62	5.1356	-4.732	-0.83917	2.634	3.3637

Device Test: 13.4 VTH_SENSE(VTH_SENSE2_FALLING/SENSE2/1.6/3/0/0/0/@VTH_SENSE)





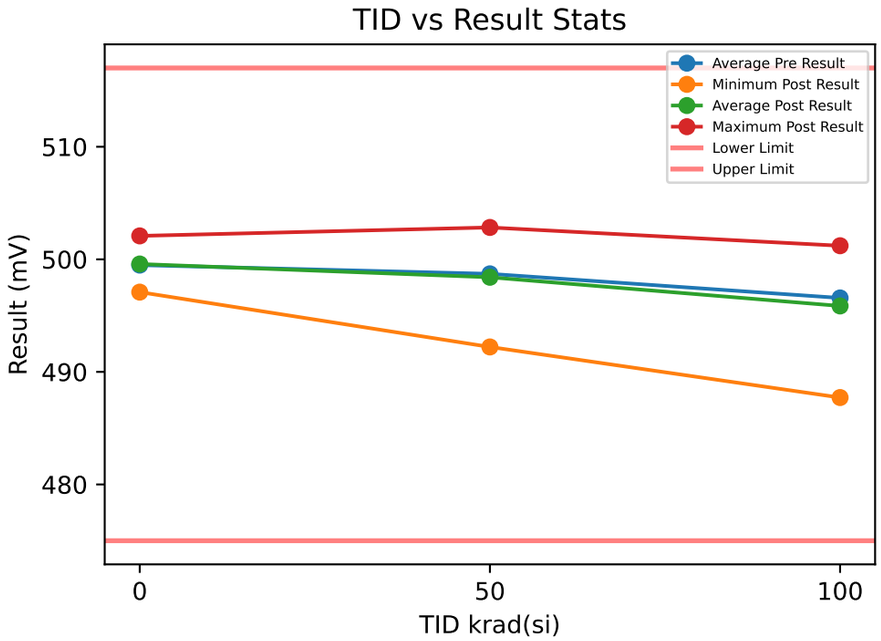
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

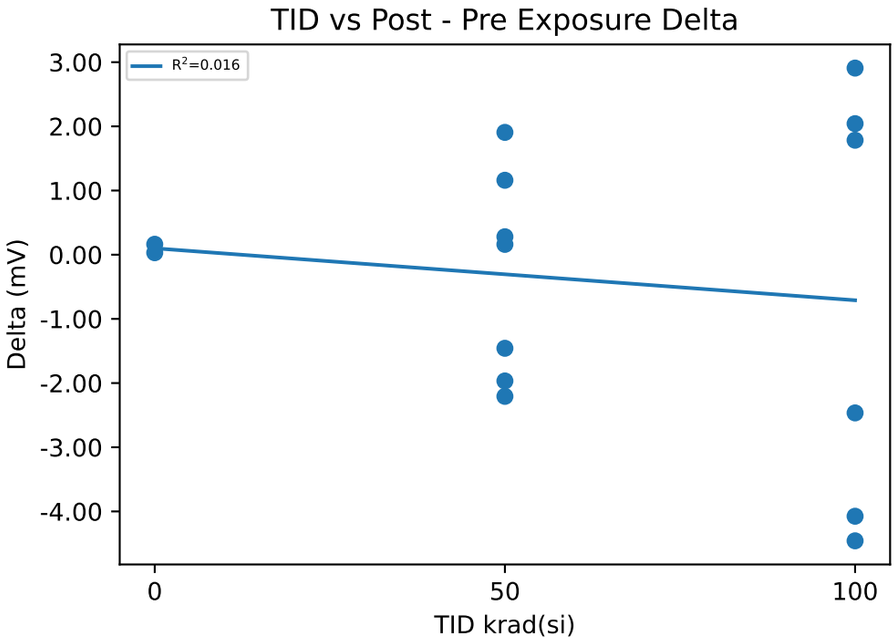
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	598.83	598.37	-0.464
89	50	Biased	600.87	599.73	-1.142
90	50	Biased	600.19	600.07	-0.124
92	50	Biased	599.17	598.71	-0.464
93	50	Unbiased	594.42	598.37	3.947
94	50	Unbiased	601.21	600.4	-0.803
95	50	Unbiased	594.76	599.05	4.287
96	100	Biased	600.53	597.69	-2.839
97	100	Biased	600.19	598.03	-2.161
98	100	Biased	595.44	600.4	4.965
99	100	Unbiased	598.49	598.37	-0.125
100	100	Unbiased	599.85	599.05	-0.803
101	100	Unbiased	598.83	597.69	-1.143
102	0	Correlation	598.83	599.39	0.554
103	0	Correlation	601.21	599.05	-2.16

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.83	600.02	601.21	1.6794	599.05	599.22	599.39	0.23971	-2.16	-0.803	0.554	1.9191
50	594.42	598.49	601.21	2.7979	598.37	599.24	600.4	0.82793	-1.142	0.74814	4.287	2.325
100	595.44	598.89	600.53	1.8635	597.69	598.54	600.4	1.0461	-2.839	-0.351	4.965	2.7788

Device Test: 13.40 VTH_SR_UVLO_FALL(VTH_SR_UVLOB_FALLING/SR_UVLOB/1.6/14/0/0/0/@VTH_SR_UVLO_FALL)





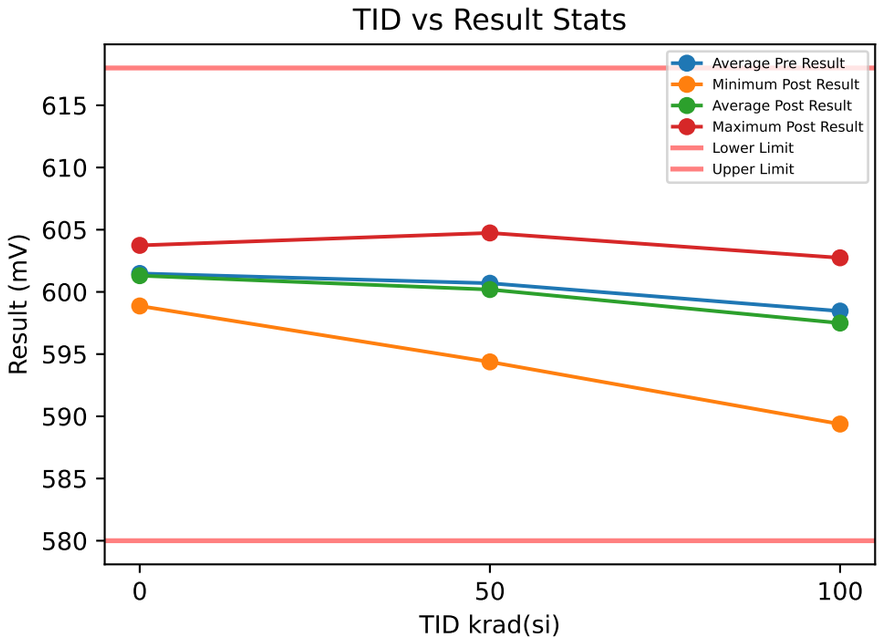
Test Results (Lower Limit = 475.0, Upper Limit = 517.0 (mV))

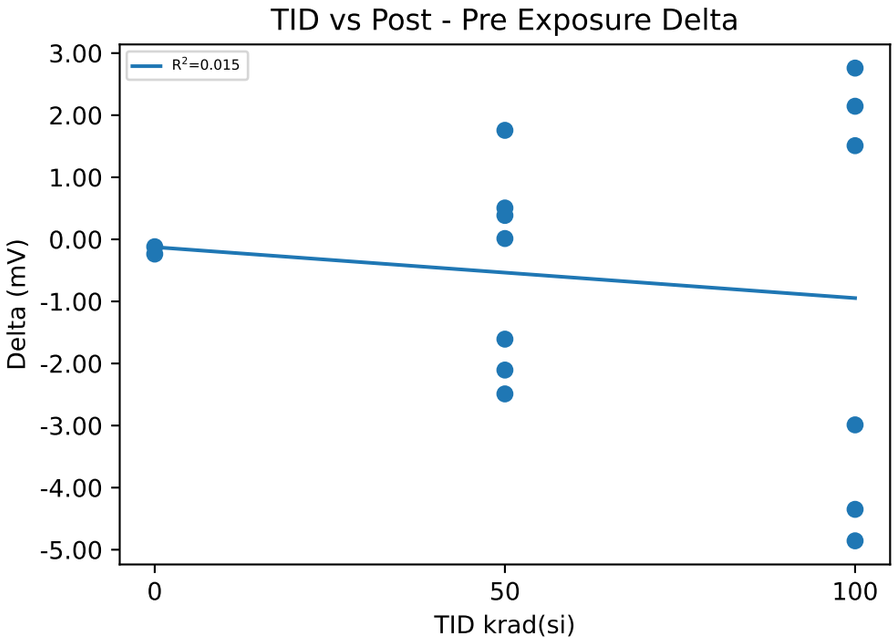
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	497.92	498.08	0.161
89	50	Biased	494.42	492.21	-2.207
90	50	Biased	502.55	502.83	0.28
92	50	Biased	501.3	499.33	-1.967
93	50	Unbiased	498.67	499.83	1.16
94	50	Unbiased	500.68	502.58	1.906
95	50	Unbiased	495.42	493.96	-1.458
96	100	Biased	500.3	497.83	-2.465
97	100	Biased	497.3	492.84	-4.458
98	100	Biased	491.8	487.72	-4.075
99	100	Unbiased	492.8	494.84	2.042
100	100	Unbiased	498.3	501.21	2.908
101	100	Unbiased	498.92	500.71	1.784
102	0	Correlation	502.05	502.08	0.031
103	0	Correlation	496.92	497.09	0.163

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	496.92	499.49	502.05	3.626	497.09	499.58	502.08	3.5327	0.031	0.097	0.163	0.093338
50	494.42	498.71	502.55	3.0316	492.21	498.41	502.83	4.043	-2.207	-0.30357	1.906	1.597
100	491.8	496.57	500.3	3.4646	487.72	495.86	501.21	5.1462	-4.458	-0.71067	2.908	3.3267

Device Test: 13.42 VTH_SR_UVLO_RISE(VTH_SR_UVLOB_RISING/SR_UVLOB/7/14/0/0/0/@VTH_SR_UVLO_RISE)





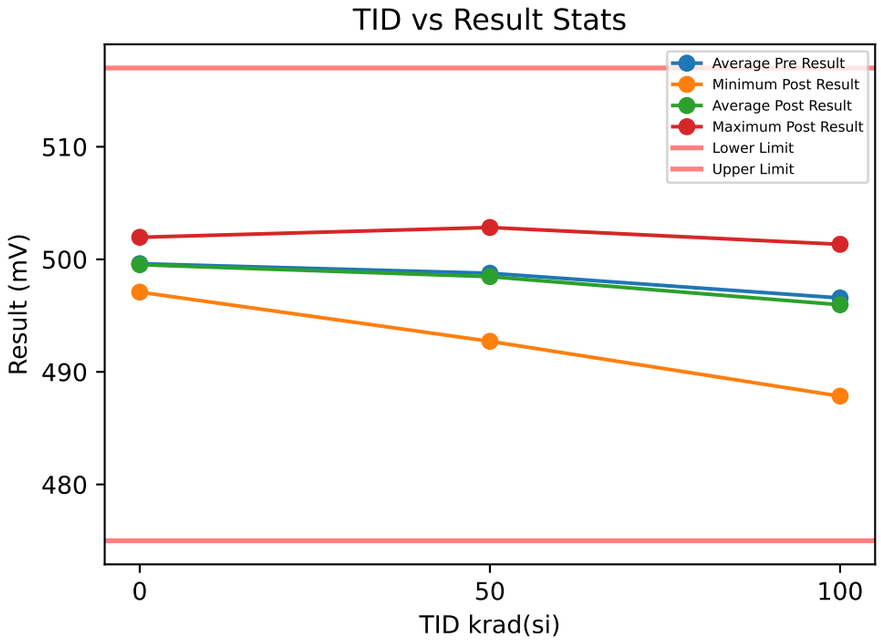
Test Results (Lower Limit = 580.0, Upper Limit = 618.0 (mV))

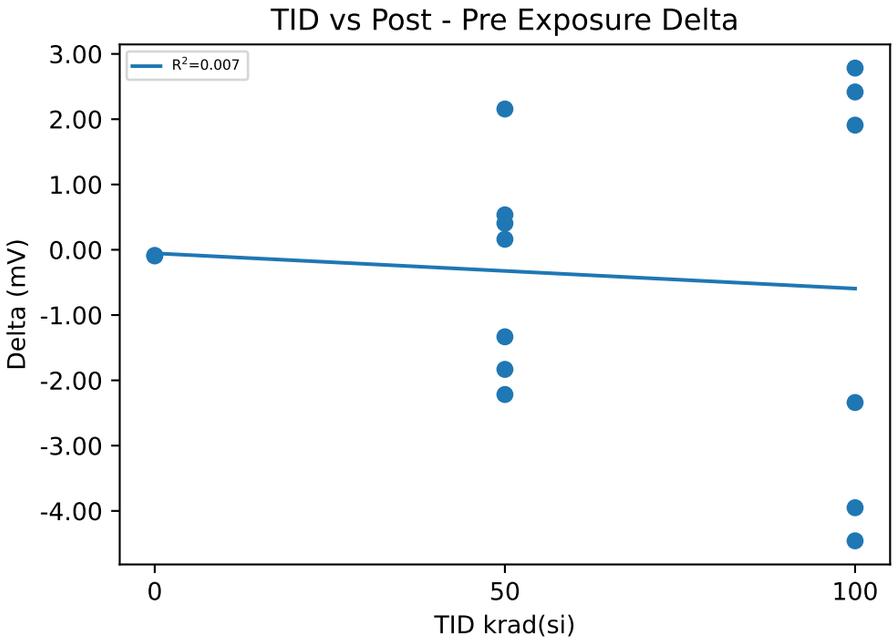
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	599.86	599.87	0.013
89	50	Biased	596.48	594.37	-2.106
90	50	Biased	604.23	604.74	0.505
92	50	Biased	603.23	600.74	-2.49
93	50	Unbiased	601.11	601.49	0.385
94	50	Unbiased	602.86	604.61	1.756
95	50	Unbiased	597.11	595.5	-1.608
96	100	Biased	602.23	599.24	-2.989
97	100	Biased	599.23	594.37	-4.857
98	100	Biased	593.73	589.38	-4.35
99	100	Unbiased	594.48	596.62	2.144
100	100	Unbiased	599.98	602.74	2.759
101	100	Unbiased	601.11	602.62	1.509
102	0	Correlation	603.86	603.74	-0.119
103	0	Correlation	599.11	598.87	-0.237

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	599.11	601.48	603.86	3.3609	598.87	601.3	603.74	3.4443	-0.237	-0.178	-0.119	0.083439
50	596.48	600.7	604.23	3.0324	594.37	600.19	604.74	4.046	-2.49	-0.50643	1.756	1.5765
100	593.73	598.46	602.23	3.5327	589.38	597.5	602.74	5.1613	-4.857	-0.964	2.759	3.4744

Device Test: 13.43 VTH_SR_UVLO_FALL(VTH_SR_UVLOB_FALLING/SR_UVLOB/7/14/0/0/0/@VTH_SR_UVLO_FALL)





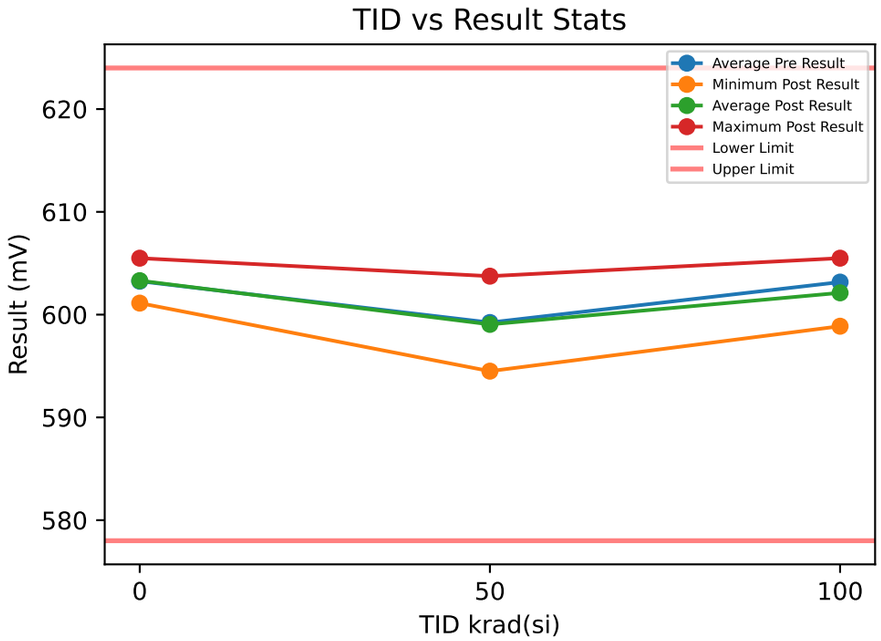
Test Results (Lower Limit = 475.0, Upper Limit = 517.0 (mV))

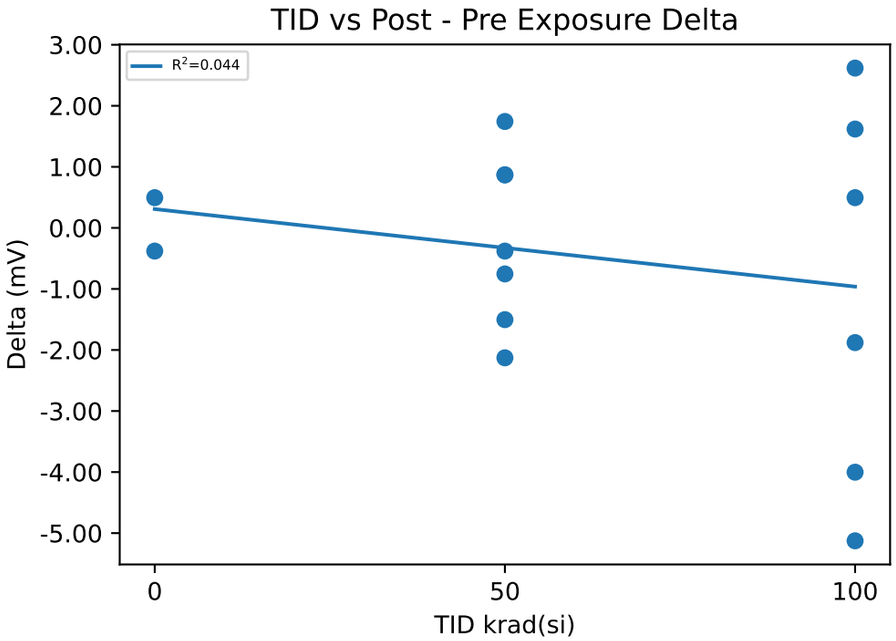
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	498.05	498.21	0.161
89	50	Biased	494.55	492.71	-1.832
90	50	Biased	502.43	502.83	0.405
92	50	Biased	501.43	499.21	-2.217
93	50	Unbiased	499.05	499.58	0.535
94	50	Unbiased	500.55	502.71	2.156
95	50	Unbiased	495.3	493.96	-1.333
96	100	Biased	500.18	497.83	-2.34
97	100	Biased	497.17	492.71	-4.458
98	100	Biased	491.8	487.84	-3.951
99	100	Unbiased	492.67	495.09	2.417
100	100	Unbiased	498.55	501.33	2.783
101	100	Unbiased	499.05	500.96	1.909
102	0	Correlation	502.05	501.96	-0.094
103	0	Correlation	497.17	497.09	-0.087

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	497.17	499.61	502.05	3.4493	497.09	499.52	501.96	3.4443	-0.094	-0.0905	-0.087	0.0049497
50	494.55	498.76	502.43	3.0023	492.71	498.46	502.83	3.9209	-2.217	-0.30357	2.156	1.556
100	491.8	496.57	500.18	3.505	487.84	495.96	501.33	5.1868	-4.458	-0.60667	2.783	3.3461

Device Test: 13.45 VTH_WDI_RISE(VTH_WDI_RISING_TM/WDI/9/5/0/0/0/@VTH_WDI_RISE)





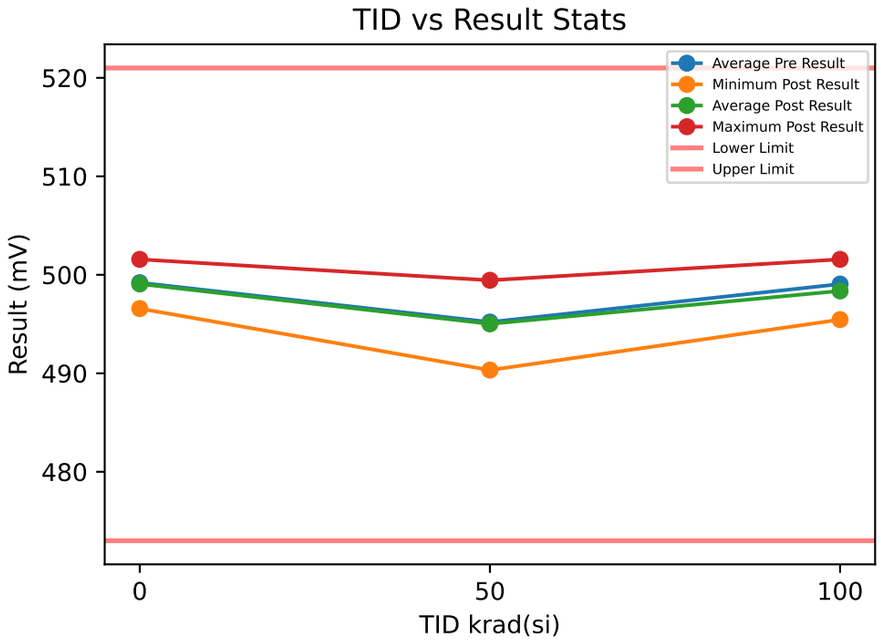
Test Results (Lower Limit = 578.0, Upper Limit = 624.0 (mV))

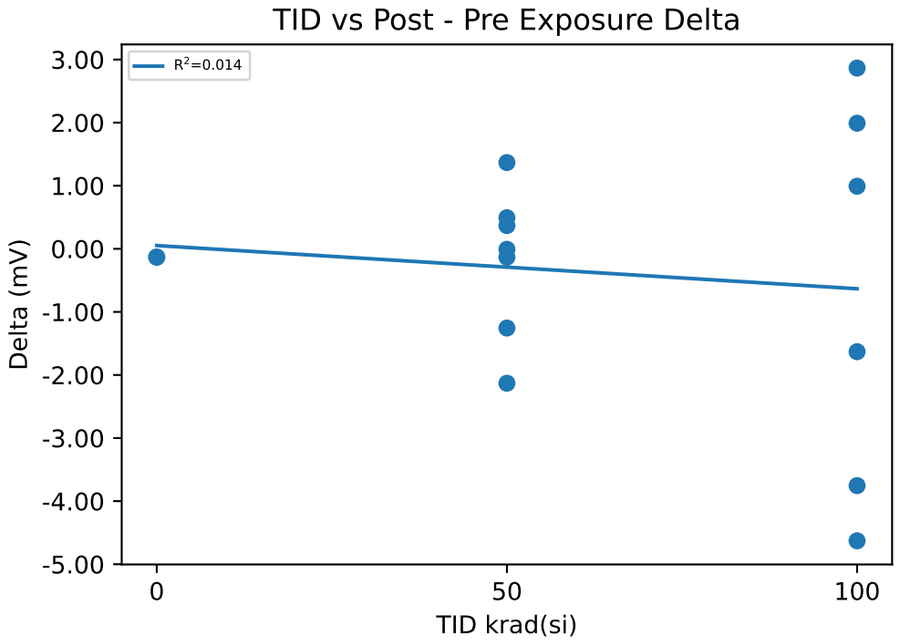
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	600.25	601.12	0.869
89	50	Biased	596.63	595.12	-1.503
90	50	Biased	598.75	598	-0.754
92	50	Biased	596.63	594.5	-2.128
93	50	Unbiased	600.38	600	-0.38
94	50	Unbiased	599.13	600.87	1.743
95	50	Unbiased	602.87	603.74	0.869
96	100	Biased	602.87	598.87	-4.002
97	100	Biased	604	598.87	-5.126
98	100	Biased	604.5	602.62	-1.879
99	100	Unbiased	603.87	605.49	1.619
100	100	Unbiased	601.25	603.87	2.618
101	100	Unbiased	602.5	602.99	0.495
102	0	Correlation	600.62	601.12	0.495
103	0	Correlation	605.87	605.49	-0.38

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	600.62	603.25	605.87	3.7102	601.12	603.31	605.49	3.0915	-0.38	0.0575	0.495	0.61872
50	596.63	599.23	602.87	2.2141	594.5	599.05	603.74	3.3598	-2.128	-0.18343	1.743	1.4032
100	601.25	603.17	604.5	1.1973	598.87	602.12	605.49	2.7032	-5.126	-1.0458	2.618	3.1299

Device Test: 13.46 VTH_WDI_FALL(VTH_WDI_FALLING_TM/WDI/9/5/0/0/0/@VTH_WDI_FALL)





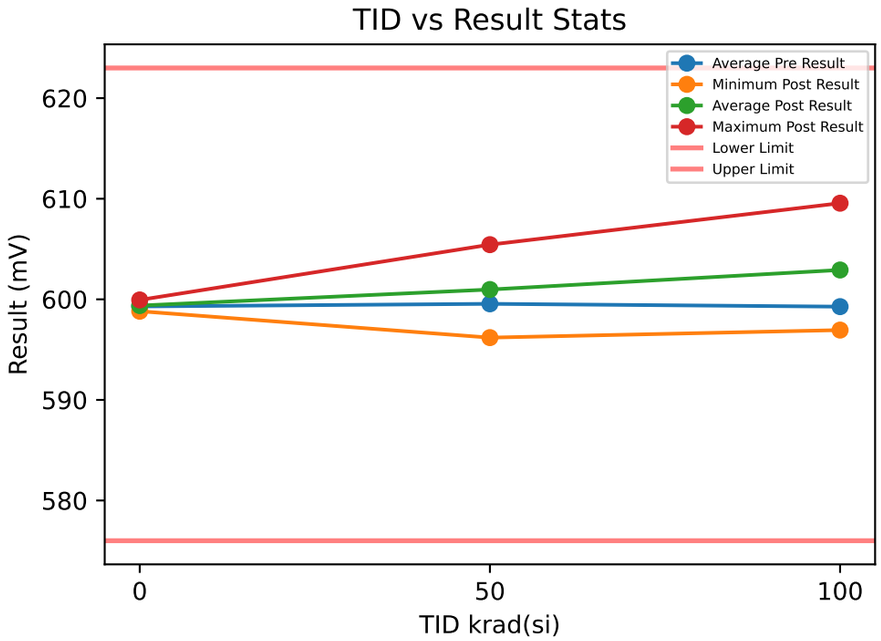
Test Results (Lower Limit = 473.0, Upper Limit = 521.0 (mV))

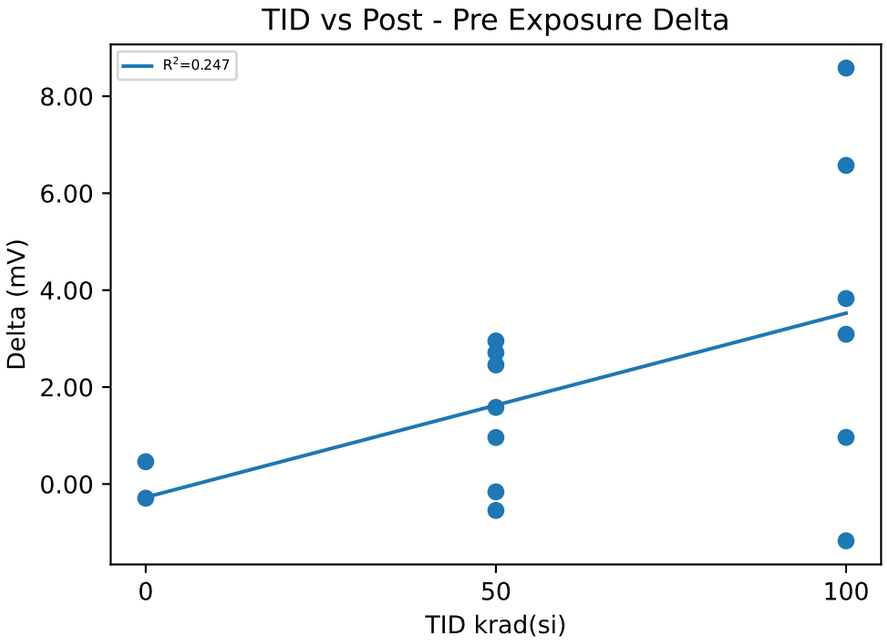
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	496.7	497.07	0.368
89	50	Biased	492.58	491.32	-1.256
90	50	Biased	494.58	494.45	-0.133
92	50	Biased	492.46	490.32	-2.131
93	50	Unbiased	496.2	496.2	-0.008
94	50	Unbiased	494.95	496.32	1.367
95	50	Unbiased	498.95	499.44	0.493
96	100	Biased	499.2	495.45	-3.754
97	100	Biased	500.08	495.45	-4.629
98	100	Biased	499.95	498.32	-1.631
99	100	Unbiased	499.58	501.57	1.991
100	100	Unbiased	497.45	500.32	2.865
101	100	Unbiased	498.08	499.07	0.992
102	0	Correlation	496.7	496.57	-0.132
103	0	Correlation	501.7	501.57	-0.132

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	496.7	499.2	501.7	3.5327	496.57	499.07	501.57	3.5327	-0.132	-0.132	-0.132	4.0194e-14
50	492.46	495.2	498.95	2.3155	490.32	495.02	499.44	3.2372	-2.131	-0.18571	1.367	1.1649
100	497.45	499.06	500.08	1.064	495.45	498.36	501.57	2.5137	-4.629	-0.69433	2.865	3.1127

Device Test: 13.48 VTH_MODE_RISE(VTH_MODE_RISING_TM/MODE/9/5/0/0/0/@VTH_MODE_RISE)





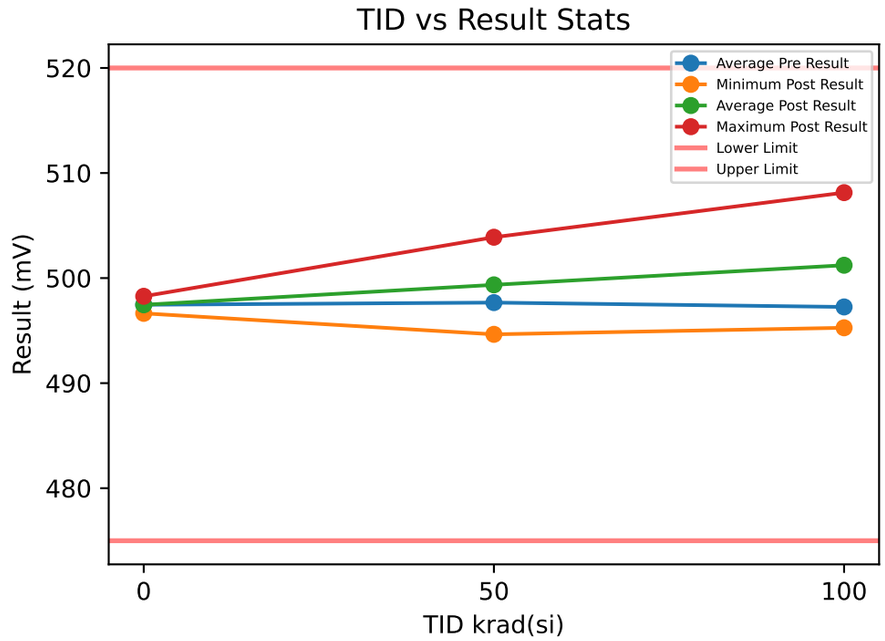
Test Results (Lower Limit = 576.0, Upper Limit = 623.0 (mV))

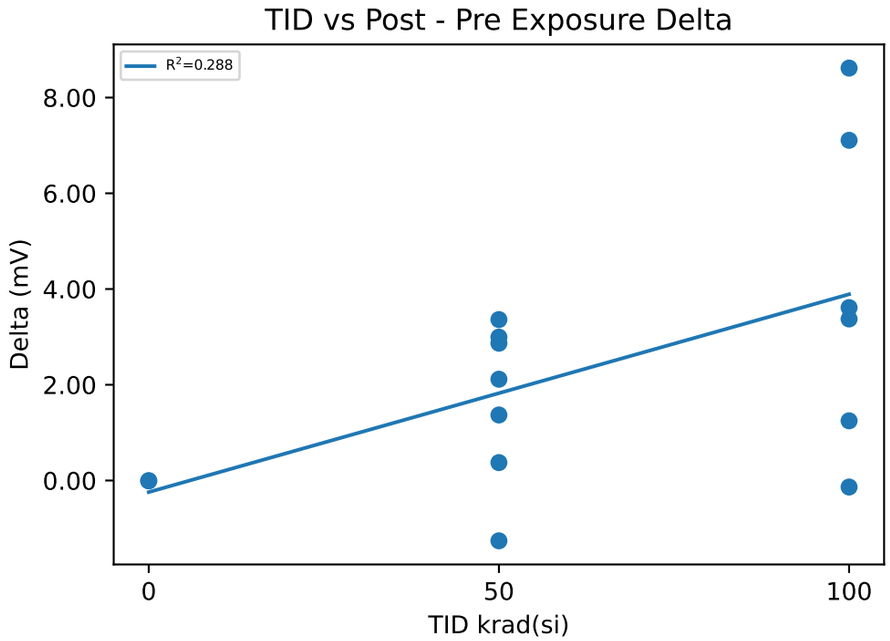
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	597.35	600.06	2.711
89	50	Biased	599.23	601.69	2.457
90	50	Biased	602.48	605.43	2.952
92	50	Biased	598.6	599.56	0.96
93	50	Unbiased	600.61	602.19	1.581
94	50	Unbiased	602.23	601.69	-0.545
95	50	Unbiased	596.35	596.19	-0.161
96	100	Biased	596.85	605.43	8.581
97	100	Biased	602.11	605.93	3.827
98	100	Biased	602.98	609.56	6.573
99	100	Unbiased	593.85	596.94	3.09
100	100	Unbiased	596.98	597.94	0.962
101	100	Unbiased	602.86	601.69	-1.171
102	0	Correlation	598.35	598.82	0.461
103	0	Correlation	600.23	599.94	-0.292

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.35	599.29	600.23	1.3272	598.82	599.38	599.94	0.79479	-0.292	0.0845	0.461	0.53245
50	596.35	599.55	602.48	2.3434	596.19	600.97	605.43	2.8303	-0.545	1.4221	2.952	1.3957
100	593.85	599.27	602.98	3.8774	596.94	602.92	609.56	4.9297	-1.171	3.6437	8.581	3.5685

Device Test: 13.49 VTH_MODE_FALL(VTH_MODE_FALLING_TM/MODE/9/5/0/0/0/@VTH_MODE_FALL)





Test Results (Lower Limit = 475.0, Upper Limit = 520.0 (mV))

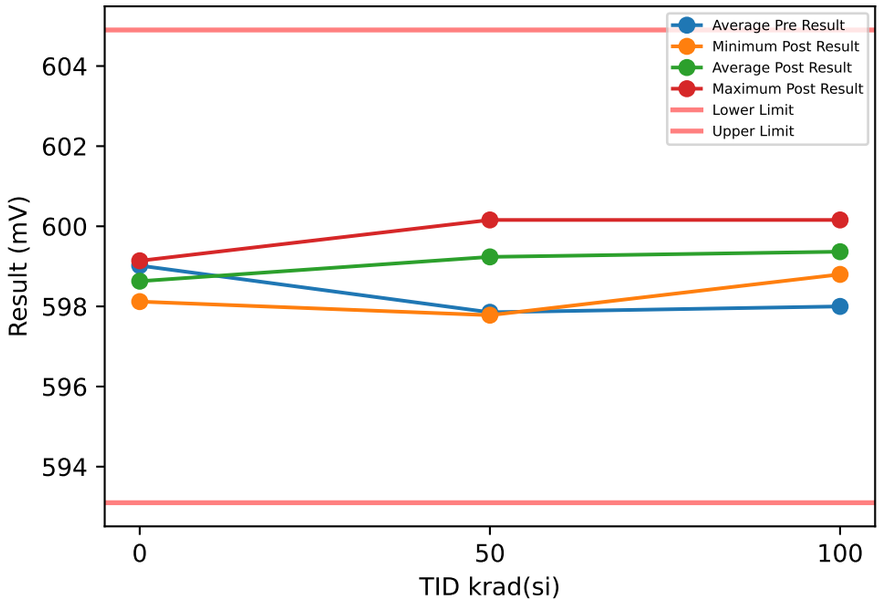
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	495.77	498.77	2.995
89	50	Biased	497.15	500.02	2.868
90	50	Biased	500.53	503.89	3.362
92	50	Biased	497.02	498.39	1.369
93	50	Unbiased	498.27	500.39	2.116
94	50	Unbiased	500.65	499.39	-1.26
95	50	Unbiased	494.27	494.64	0.374
96	100	Biased	494.9	503.51	8.616
97	100	Biased	500.28	503.89	3.612
98	100	Biased	501.03	508.13	7.107
99	100	Unbiased	491.89	495.27	3.375
100	100	Unbiased	495.02	496.27	1.247
101	100	Unbiased	500.4	500.26	-0.136
102	0	Correlation	496.65	496.64	-0.005
103	0	Correlation	498.27	498.27	-0.007

Test Statistics (mV)

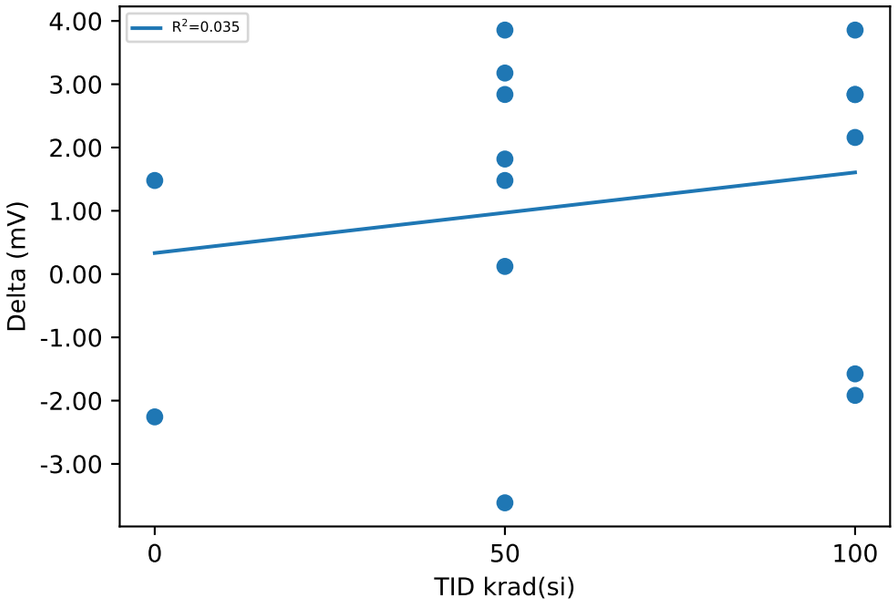
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	496.65	497.46	498.27	1.1498	496.64	497.45	498.27	1.1483	-0.007	-0.006	-0.005	0.0014142
50	494.27	497.67	500.65	2.3542	494.64	499.36	503.89	2.7542	-1.26	1.6891	3.362	1.6636
100	491.89	497.25	501.03	3.8089	495.27	501.22	508.13	4.9197	-0.136	3.9702	8.616	3.3521

Device Test: 13.5 VTH_SENSE(VTH_SENSE3_RISING/SENSE3/1.6/3/0/0/0/@VTH_SENSE)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



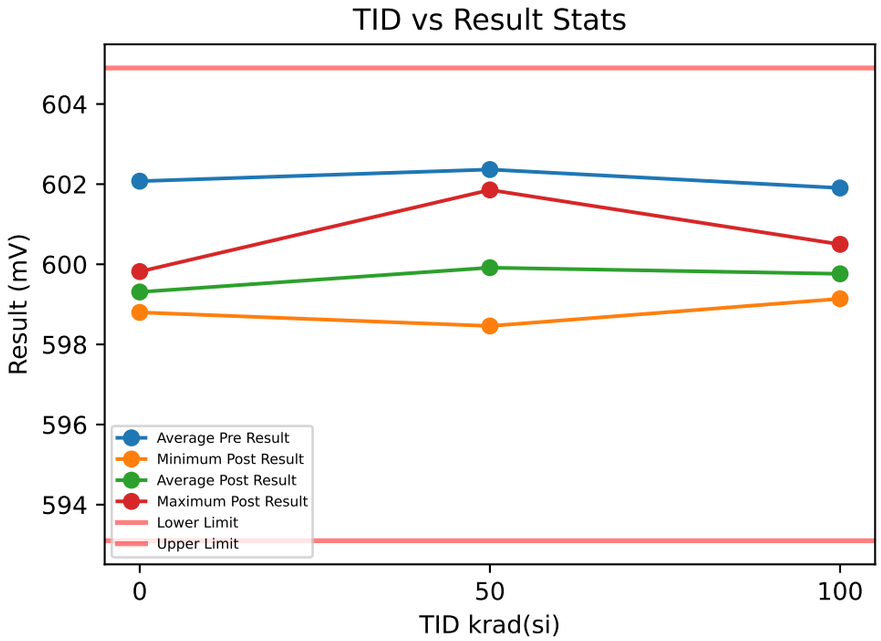
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

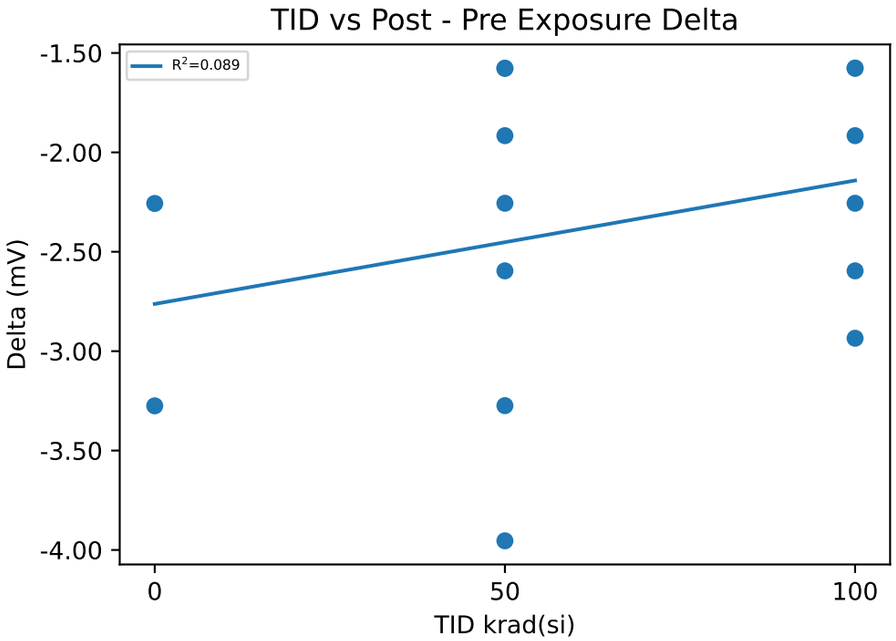
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	596.98	598.8	1.818
89	50	Biased	595.96	599.82	3.856
90	50	Biased	600.04	600.16	0.121
92	50	Biased	596.64	599.48	2.838
93	50	Unbiased	596.3	597.78	1.479
94	50	Unbiased	596.64	599.82	3.177
95	50	Unbiased	602.41	598.8	-3.615
96	100	Biased	595.96	598.8	2.837
97	100	Biased	595.28	599.14	3.856
98	100	Biased	597.32	600.16	2.838
99	100	Unbiased	601.06	599.48	-1.577
100	100	Unbiased	601.06	599.14	-1.917
101	100	Unbiased	597.32	599.48	2.159
102	0	Correlation	600.38	598.12	-2.257
103	0	Correlation	597.66	599.14	1.479

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	597.66	599.02	600.38	1.9212	598.12	598.63	599.14	0.72054	-2.257	-0.389	1.479	2.6418
50	595.96	597.85	602.41	2.4239	597.78	599.24	600.16	0.82518	-3.615	1.382	3.856	2.524
100	595.28	598	601.06	2.4955	598.8	599.37	600.16	0.46419	-1.917	1.366	3.856	2.4738

Device Test: 13.6 VTH_SENSE(VTH_SENSE3_FALLING/SENSE3/1.6/3/0/0/0/@VTH_SENSE)





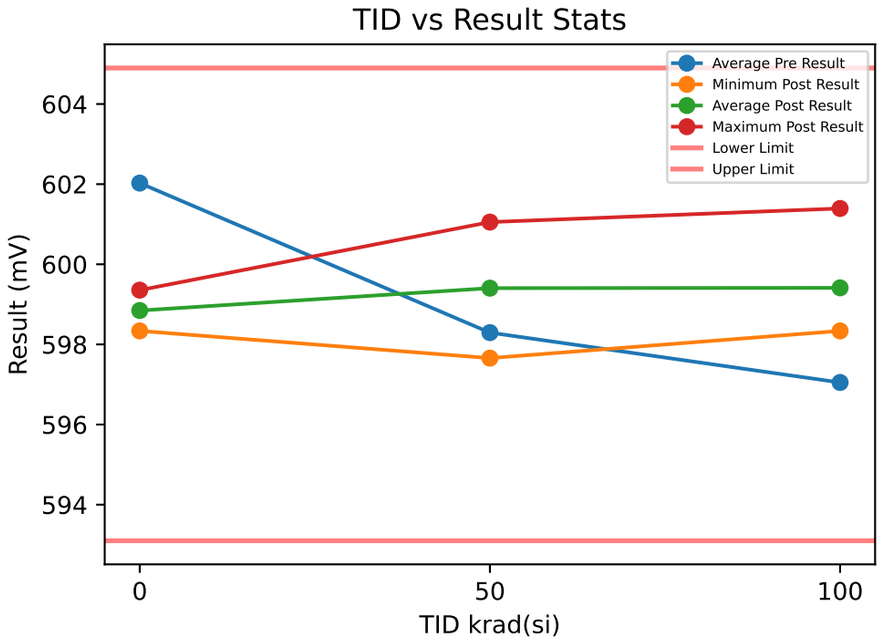
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

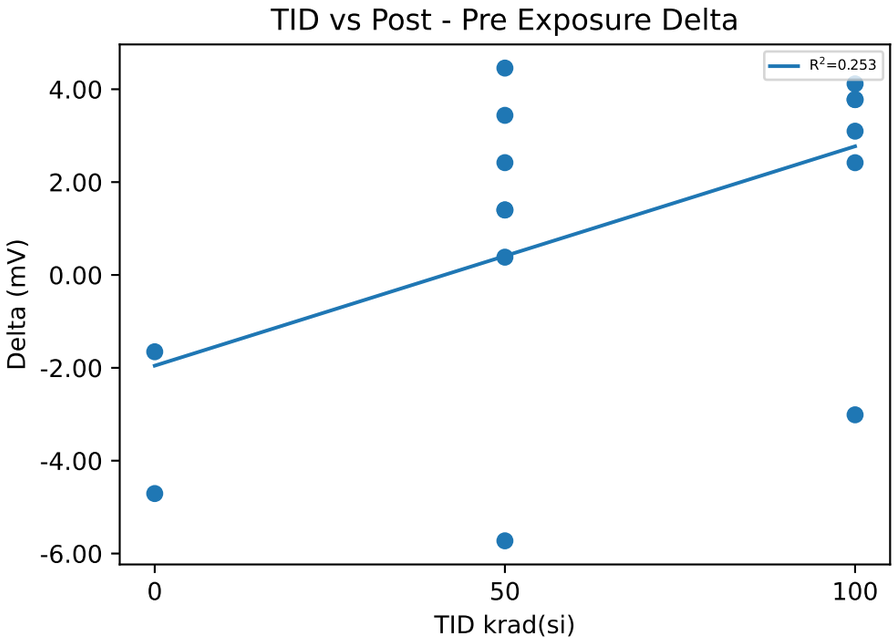
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	601.39	599.48	-1.916
89	50	Biased	603.77	600.5	-3.274
90	50	Biased	604.11	601.86	-2.256
92	50	Biased	602.41	599.82	-2.596
93	50	Unbiased	600.04	598.46	-1.577
94	50	Unbiased	601.74	600.16	-1.577
95	50	Unbiased	603.09	599.14	-3.954
96	100	Biased	602.41	600.5	-1.916
97	100	Biased	601.06	599.48	-1.577
98	100	Biased	602.07	600.5	-1.576
99	100	Unbiased	602.41	599.48	-2.935
100	100	Unbiased	601.74	599.48	-2.256
101	100	Unbiased	601.74	599.14	-2.596
102	0	Correlation	601.06	598.8	-2.257
103	0	Correlation	603.09	599.82	-3.275

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	601.06	602.07	603.09	1.4404	598.8	599.31	599.82	0.72054	-3.275	-2.766	-2.257	0.71983
50	600.04	602.37	604.11	1.433	598.46	599.92	601.86	1.0867	-3.954	-2.45	-1.577	0.8953
100	601.06	601.9	602.41	0.51484	599.14	599.76	600.5	0.58511	-2.935	-2.1427	-1.576	0.55473

Device Test: 13.7 VTH_SENSE(VTH_SENSE4_RISING/SENSE4/1.6/3/0/0/0/@VTH_SENSE)





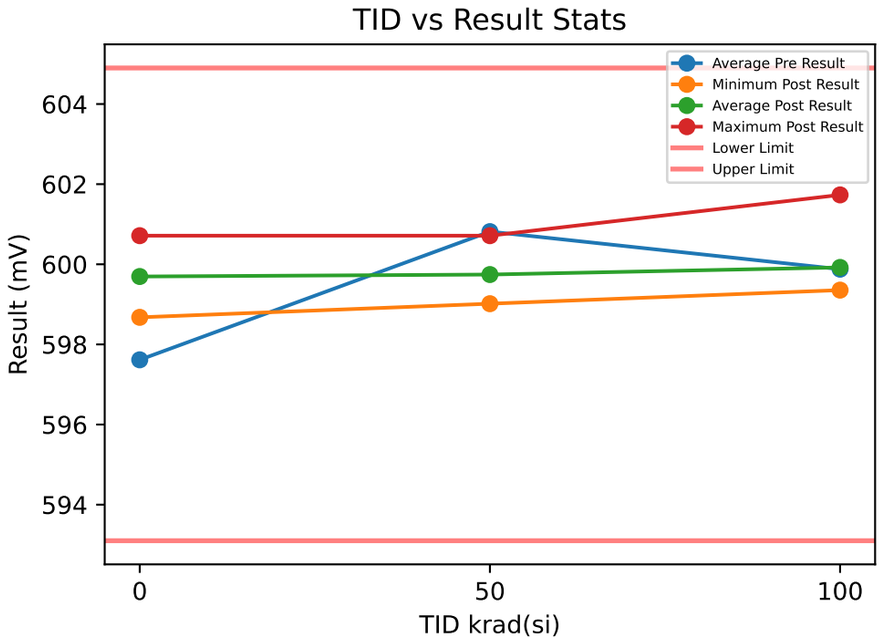
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

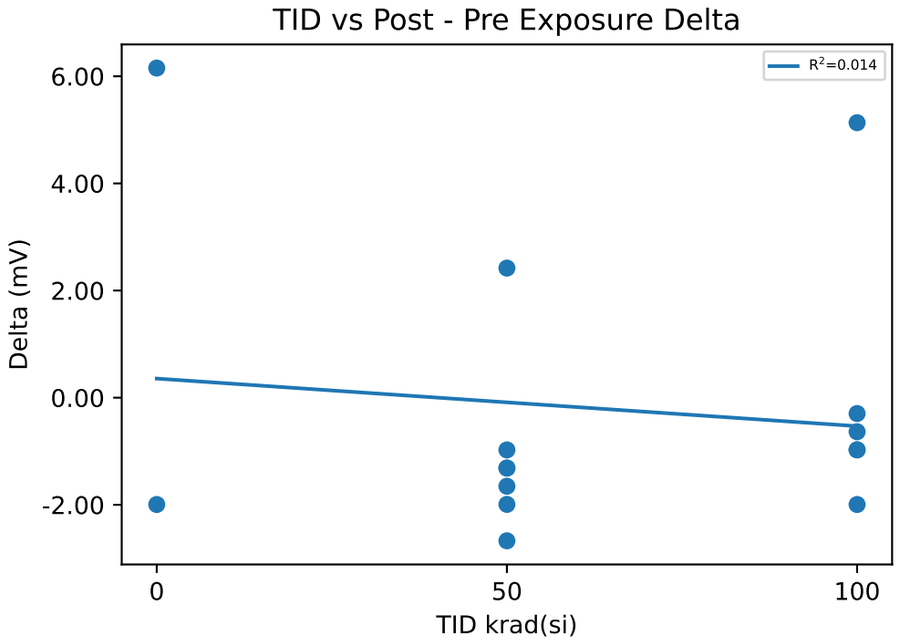
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	595.58	600.03	4.456
89	50	Biased	599.65	600.03	0.383
90	50	Biased	596.6	600.03	3.438
92	50	Biased	597.28	598.68	1.4
93	50	Unbiased	596.26	597.66	1.4
94	50	Unbiased	598.63	601.05	2.419
95	50	Unbiased	604.06	598.34	-5.726
96	100	Biased	595.92	598.34	2.418
97	100	Biased	595.58	599.7	4.116
98	100	Biased	597.62	601.39	3.777
99	100	Unbiased	595.24	598.34	3.097
100	100	Unbiased	596.26	600.03	3.777
101	100	Unbiased	601.69	598.68	-3.012
102	0	Correlation	603.04	598.34	-4.708
103	0	Correlation	601.01	599.36	-1.654

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	601.01	602.03	603.04	1.4397	598.34	598.85	599.36	0.71983	-4.708	-3.181	-1.654	2.1595
50	595.58	598.29	604.06	2.9061	597.66	599.4	601.05	1.1994	-5.726	1.11	4.456	3.3105
100	595.24	597.05	601.69	2.4157	598.34	599.41	601.39	1.2038	-3.012	2.3622	4.116	2.702

Device Test: 13.8 VTH_SENSE(VTH_SENSE4_FALLING/SENSE4/1.6/3/0/0/0/@VTH_SENSE)





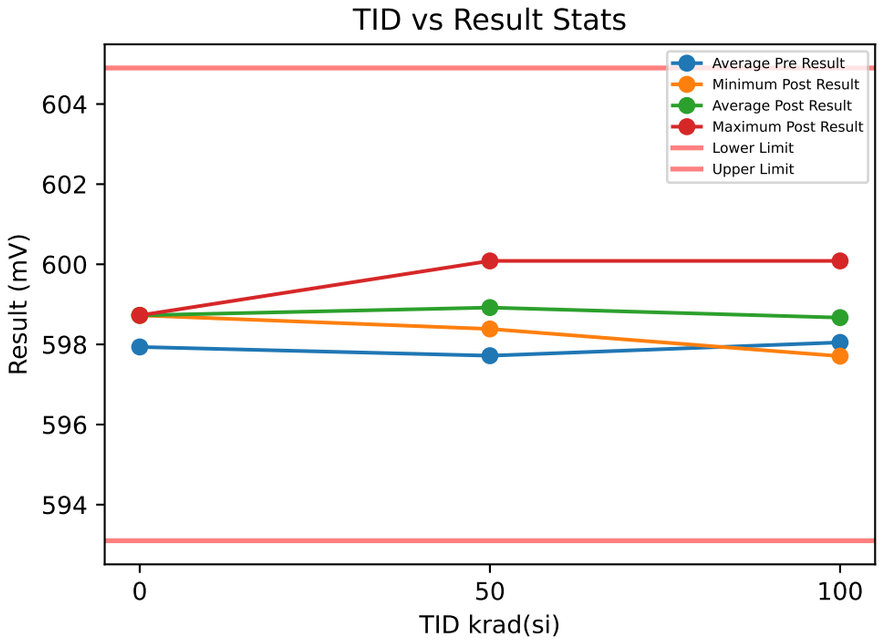
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

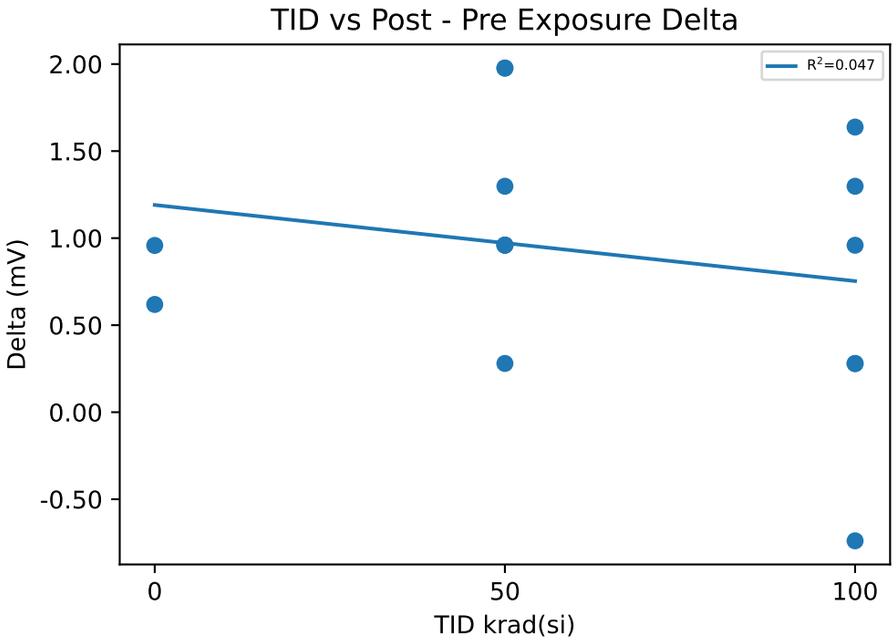
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	600.67	599.7	-0.975
89	50	Biased	601.35	600.03	-1.314
90	50	Biased	602.71	600.71	-1.992
92	50	Biased	601.69	599.02	-2.672
93	50	Unbiased	596.6	599.02	2.419
94	50	Unbiased	602.37	600.71	-1.653
95	50	Unbiased	600.33	599.02	-1.314
96	100	Biased	599.99	599.36	-0.636
97	100	Biased	601.35	599.36	-1.994
98	100	Biased	602.71	601.73	-0.974
99	100	Unbiased	594.22	599.36	5.133
100	100	Unbiased	601.01	600.03	-0.974
101	100	Unbiased	599.99	599.7	-0.296
102	0	Correlation	600.67	598.68	-1.994
103	0	Correlation	594.56	600.71	6.153

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	594.56	597.62	600.67	4.3197	598.68	599.7	600.71	1.4411	-1.994	2.0795	6.153	5.7608
50	596.6	600.82	602.71	2.0445	599.02	599.74	600.71	0.77016	-2.672	-1.0716	2.419	1.6359
100	594.22	599.88	602.71	2.9481	599.36	599.92	601.73	0.92789	-1.994	0.043167	5.133	2.5574

Device Test: 13.9 VTH_SENSE(VTH_SENSE1_RISING/SENSE1/7/3/0/0/0/@VTH_SENSE)





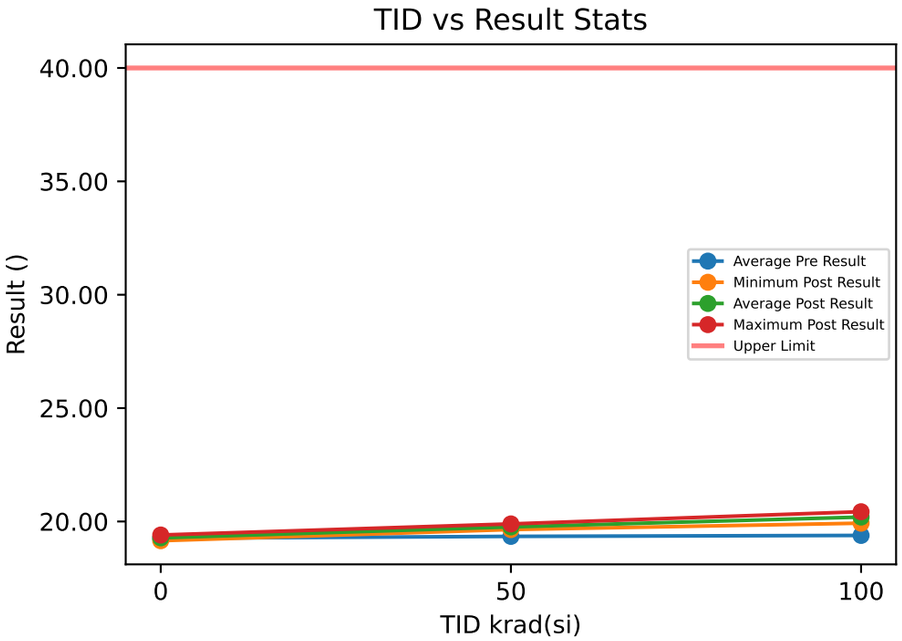
Test Results (Lower Limit = 593.1, Upper Limit = 604.9 (mV))

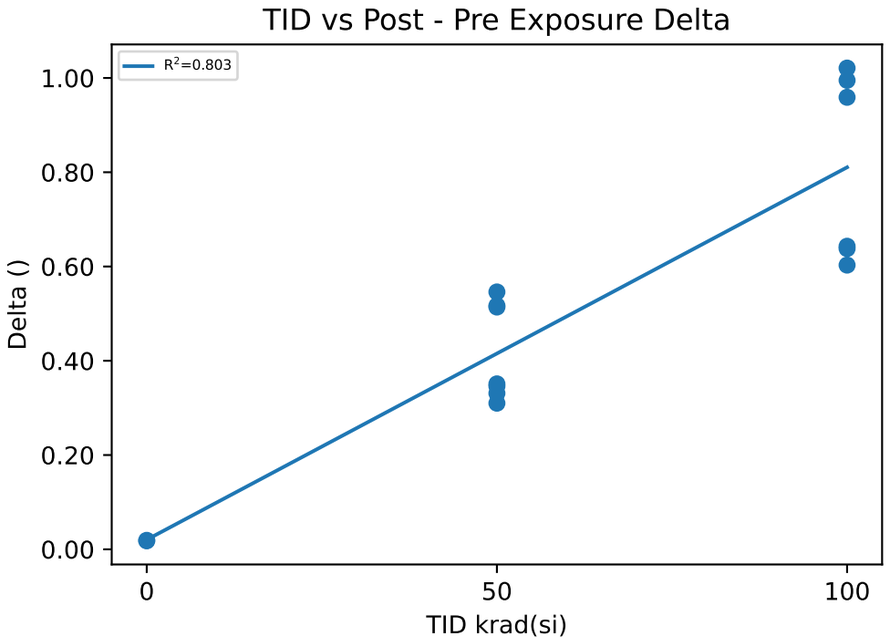
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	596.75	598.73	1.977
89	50	Biased	598.11	598.39	0.28
90	50	Biased	599.12	600.08	0.96
92	50	Biased	597.09	598.39	1.298
93	50	Unbiased	596.41	598.39	1.977
94	50	Unbiased	599.12	600.08	0.96
95	50	Unbiased	597.43	598.39	0.959
96	100	Biased	598.45	597.71	-0.739
97	100	Biased	597.43	598.73	1.298
98	100	Biased	598.11	598.39	0.28
99	100	Unbiased	597.77	598.05	0.279
100	100	Unbiased	598.45	600.08	1.638
101	100	Unbiased	598.11	599.07	0.959
102	0	Correlation	598.11	598.73	0.619
103	0	Correlation	597.77	598.73	0.958

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	597.77	597.94	598.11	0.23971	598.73	598.73	598.73	0	0.619	0.7885	0.958	0.23971
50	596.41	597.72	599.12	1.0985	598.39	598.92	600.08	0.80503	0.28	1.2016	1.977	0.61056
100	597.43	598.05	598.45	0.39702	597.71	598.67	600.08	0.84331	-0.739	0.61917	1.638	0.85903

Device Test: 18.0 RESET_RPMOS_LOW_V(Res_PU_RESETB1/RESETB1/1.6/3/0/0/2/@RESET_RPMOS_LOW_V)





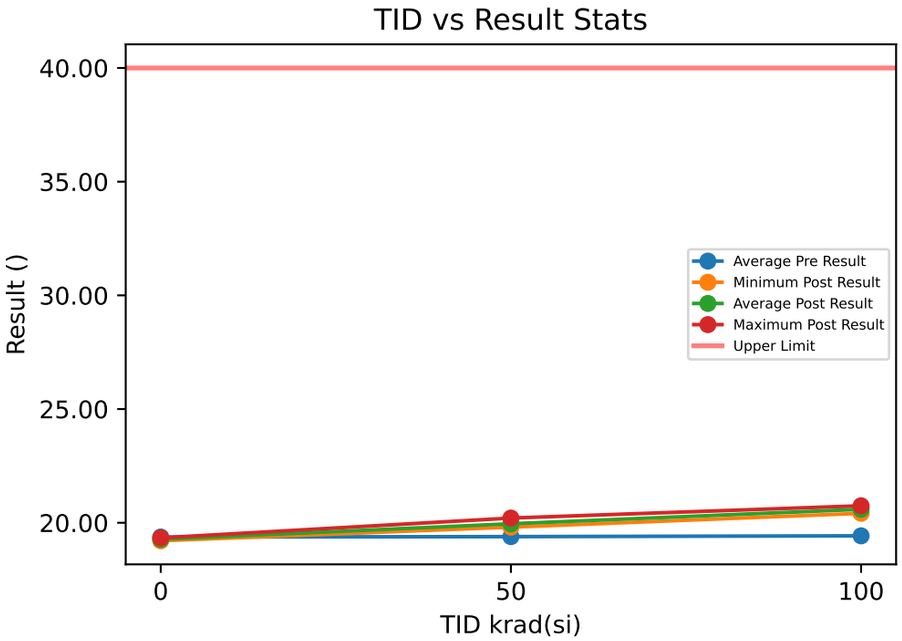
Test Results (Upper Limit = 40.0 ())

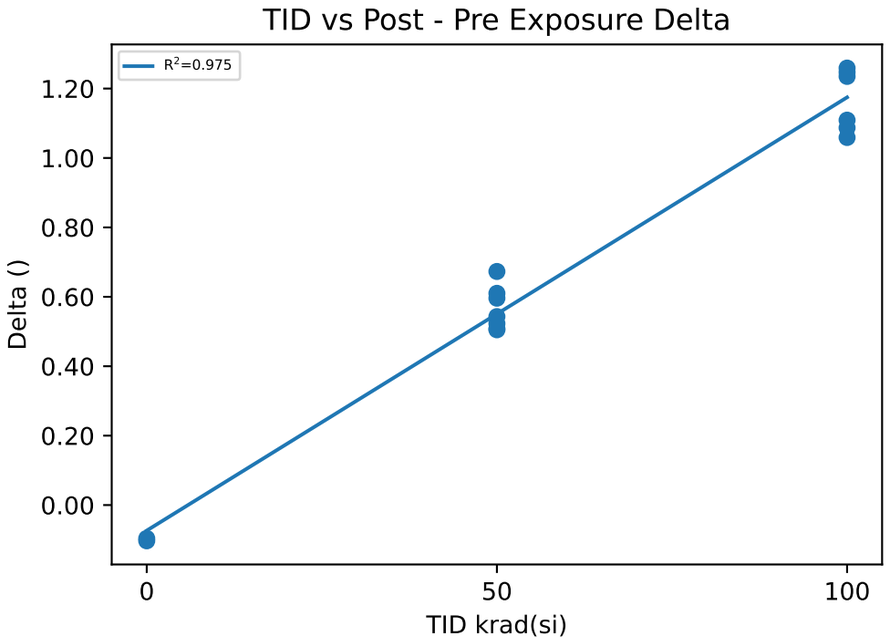
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.431	19.741	0.31
89	50	Biased	19.301	19.647	0.346
90	50	Biased	19.313	19.644	0.331
92	50	Biased	19.542	19.893	0.351
93	50	Unbiased	19.327	19.873	0.546
94	50	Unbiased	19.3	19.814	0.514
95	50	Unbiased	19.192	19.709	0.517
96	100	Biased	19.398	20.036	0.638
97	100	Biased	19.363	20.006	0.643
98	100	Biased	19.322	19.925	0.603
99	100	Unbiased	19.393	20.352	0.959
100	100	Unbiased	19.436	20.431	0.995
101	100	Unbiased	19.4	20.421	1.021
102	0	Correlation	19.134	19.152	0.018
103	0	Correlation	19.385	19.404	0.019

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.134	19.26	19.385	0.17748	19.152	19.278	19.404	0.17819	0.018	0.0185	0.019	0.00070711
50	19.192	19.344	19.542	0.11174	19.644	19.76	19.893	0.10211	0.31	0.41643	0.546	0.10351
100	19.322	19.385	19.436	0.038759	19.925	20.195	20.431	0.23036	0.603	0.80983	1.021	0.20063

Device Test: 18.1 RESET_RPMOS_LOW_V(Res_PU_RESETB2/RESETB2/1.6/3/0/0/2/@RESET_RPMOS_LOW_V)





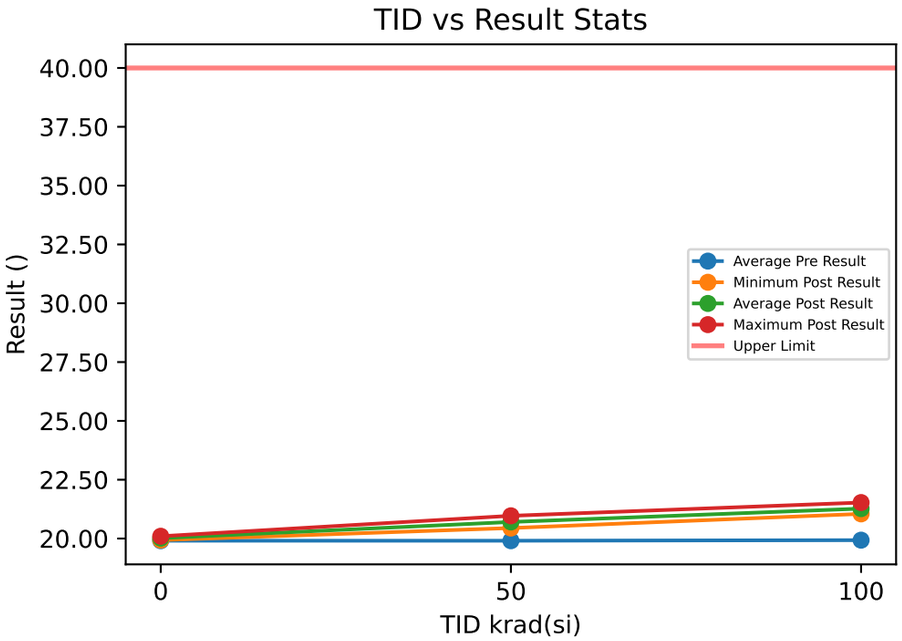
Test Results (Upper Limit = 40.0 ())

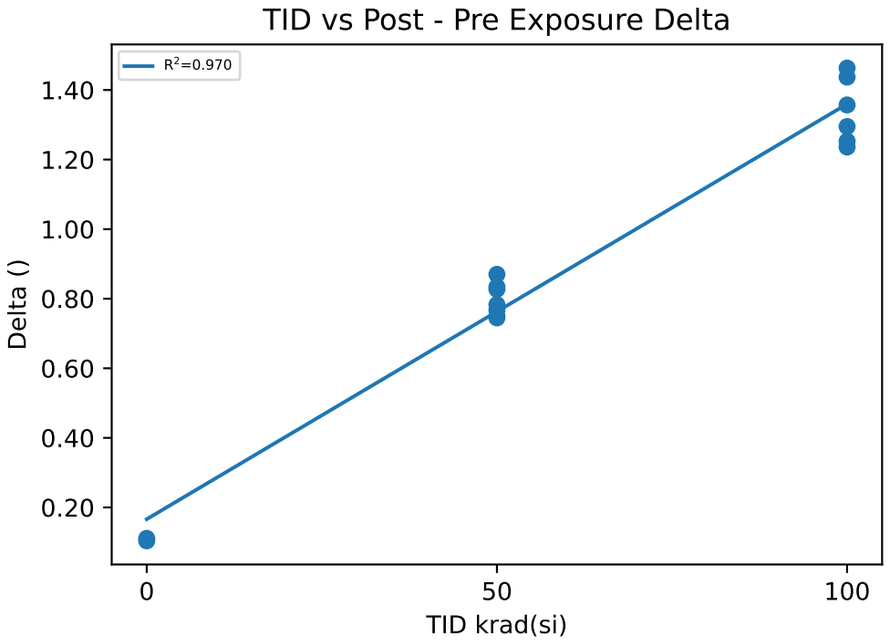
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.328	19.851	0.523
89	50	Biased	19.245	19.855	0.61
90	50	Biased	19.417	20.013	0.596
92	50	Biased	19.533	20.206	0.673
93	50	Unbiased	19.499	20.042	0.543
94	50	Unbiased	19.299	19.807	0.508
95	50	Unbiased	19.407	19.912	0.505
96	100	Biased	19.409	20.644	1.235
97	100	Biased	19.487	20.746	1.259
98	100	Biased	19.382	20.629	1.247
99	100	Unbiased	19.356	20.415	1.059
100	100	Unbiased	19.498	20.585	1.087
101	100	Unbiased	19.418	20.527	1.109
102	0	Correlation	19.313	19.21	-0.103
103	0	Correlation	19.431	19.335	-0.096

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.313	19.372	19.431	0.083439	19.21	19.273	19.335	0.088388	-0.103	-0.0995	-0.096	0.0049497
50	19.245	19.39	19.533	0.10528	19.807	19.955	20.206	0.14054	0.505	0.56543	0.673	0.06291
100	19.356	19.425	19.498	0.056724	20.415	20.591	20.746	0.11259	1.059	1.166	1.259	0.090454

Device Test: 18.10 PWRGD_RPMOS_LOW_V(Res_PU_PWRDG/PWRGD/1.6/14/0/0/2/@PWRGD_RPMOS_LOW_V)





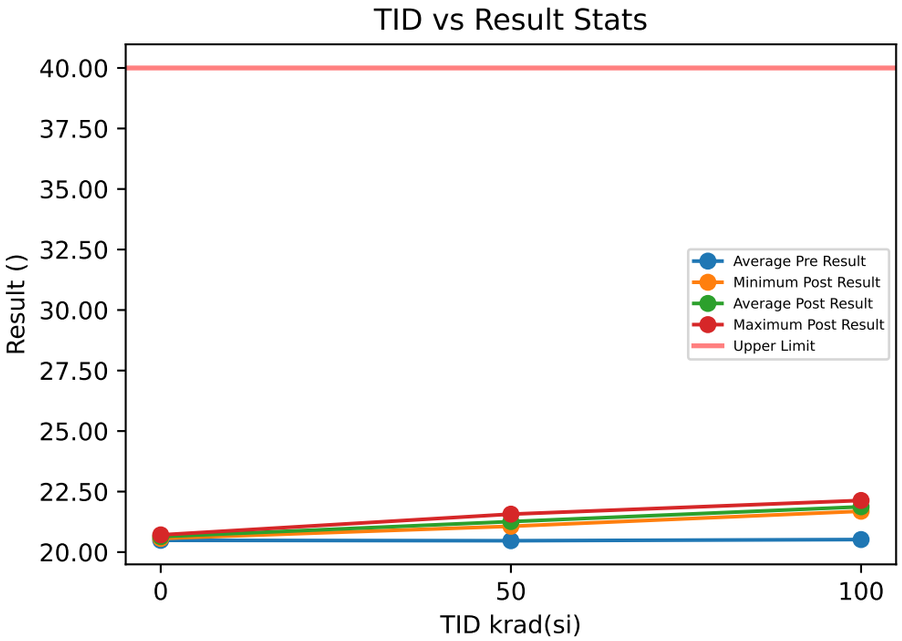
Test Results (Upper Limit = 40.0 ())

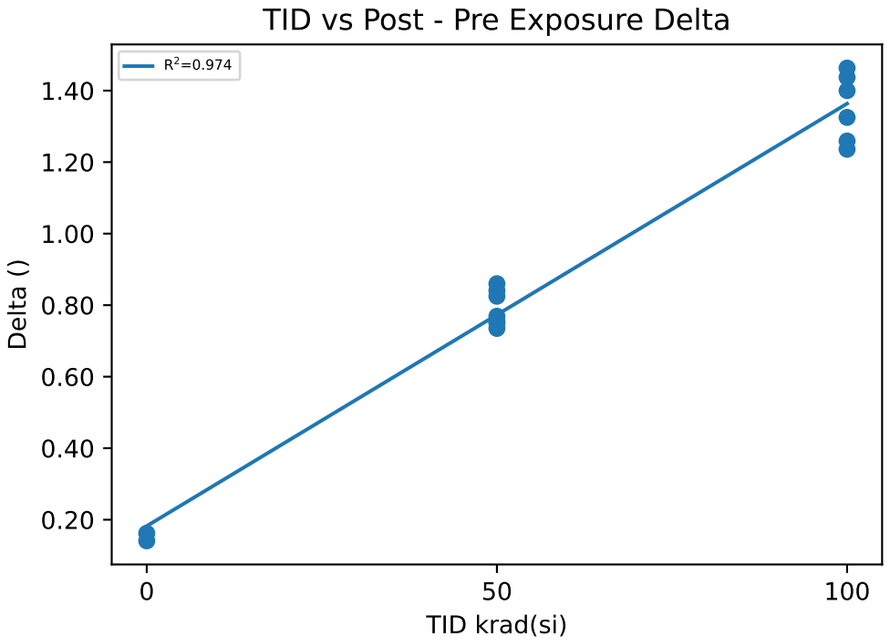
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.83	20.597	0.767
89	50	Biased	19.719	20.546	0.827
90	50	Biased	19.845	20.679	0.834
92	50	Biased	20.096	20.966	0.87
93	50	Unbiased	20.085	20.868	0.783
94	50	Unbiased	19.701	20.446	0.745
95	50	Unbiased	20.072	20.822	0.75
96	100	Biased	19.778	21.135	1.357
97	100	Biased	20.066	21.529	1.463
98	100	Biased	19.941	21.378	1.437
99	100	Unbiased	19.812	21.048	1.236
100	100	Unbiased	19.904	21.157	1.253
101	100	Unbiased	20.083	21.378	1.295
102	0	Correlation	19.829	19.933	0.104
103	0	Correlation	19.986	20.097	0.111

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.829	19.907	19.986	0.11102	19.933	20.015	20.097	0.11597	0.104	0.1075	0.111	0.0049497
50	19.701	19.907	20.096	0.17425	20.446	20.703	20.966	0.18844	0.745	0.79657	0.87	0.04762
100	19.778	19.931	20.083	0.12628	21.048	21.271	21.529	0.18476	1.236	1.3402	1.463	0.095118

Device Test: 18.11 WDO_RPMOS_LOW_V(Res_PU_WDOB/WDOB/1.6/14/0/0/2/@WDO_RPMOS_LOW_V)





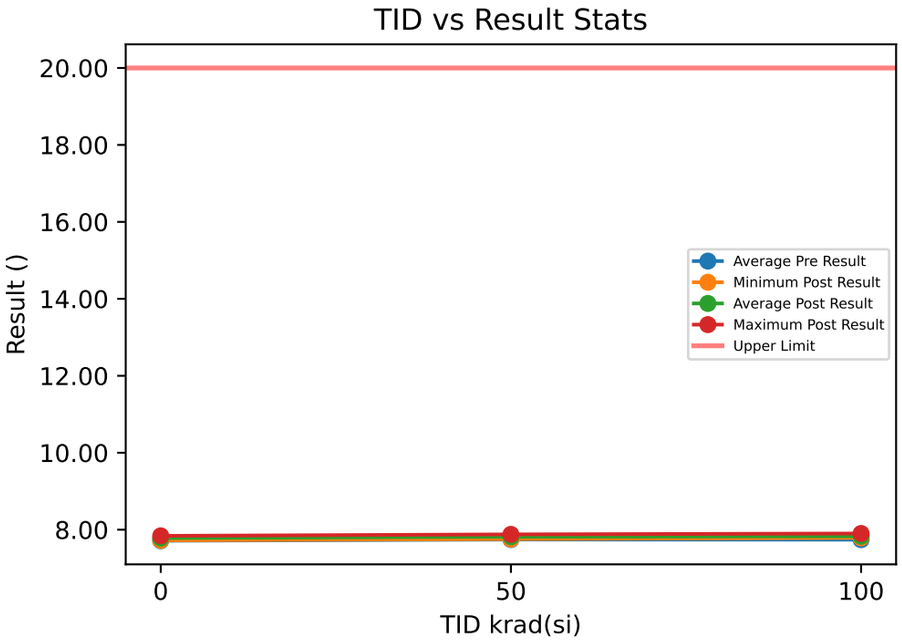
Test Results (Upper Limit = 40.0 ())

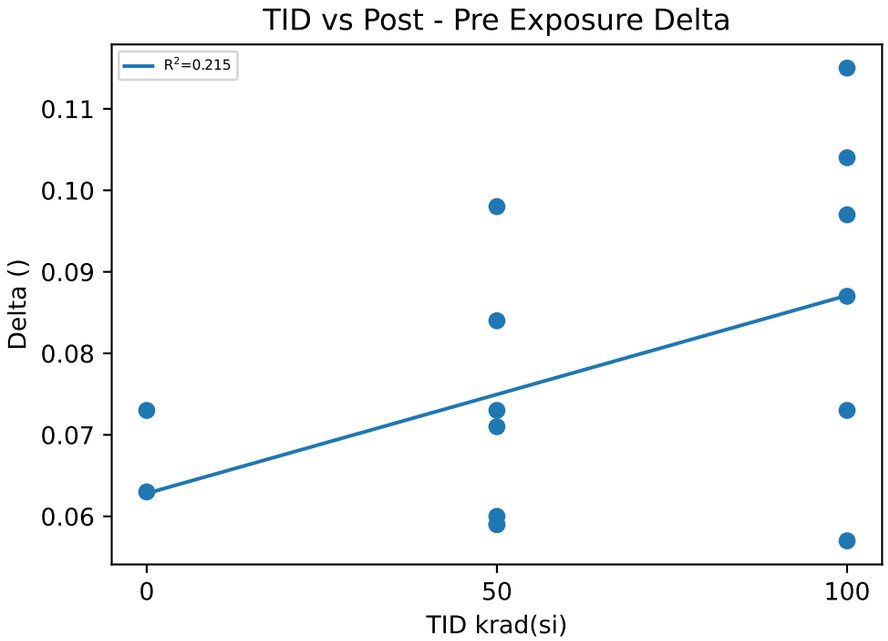
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	20.33	21.084	0.754
89	50	Biased	20.298	21.123	0.825
90	50	Biased	20.432	21.273	0.841
92	50	Biased	20.708	21.568	0.86
93	50	Unbiased	20.636	21.405	0.769
94	50	Unbiased	20.317	21.067	0.75
95	50	Unbiased	20.57	21.305	0.735
96	100	Biased	20.424	21.824	1.4
97	100	Biased	20.67	22.133	1.463
98	100	Biased	20.475	21.912	1.437
99	100	Unbiased	20.452	21.688	1.236
100	100	Unbiased	20.522	21.781	1.259
101	100	Unbiased	20.567	21.892	1.325
102	0	Correlation	20.423	20.564	0.141
103	0	Correlation	20.549	20.711	0.162

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.423	20.486	20.549	0.089095	20.564	20.637	20.711	0.10394	0.141	0.1515	0.162	0.014849
50	20.298	20.47	20.708	0.16745	21.067	21.261	21.568	0.18488	0.735	0.79057	0.86	0.050143
100	20.424	20.518	20.67	0.090068	21.688	21.872	22.133	0.15137	1.236	1.3533	1.463	0.094523

Device Test: 18.12 RESET_RPMOS_HIGH_V(Res_PU_RESETB1/RESETB1/7/3/0/0/2/@RESET_RPMOS_HIGH_V)





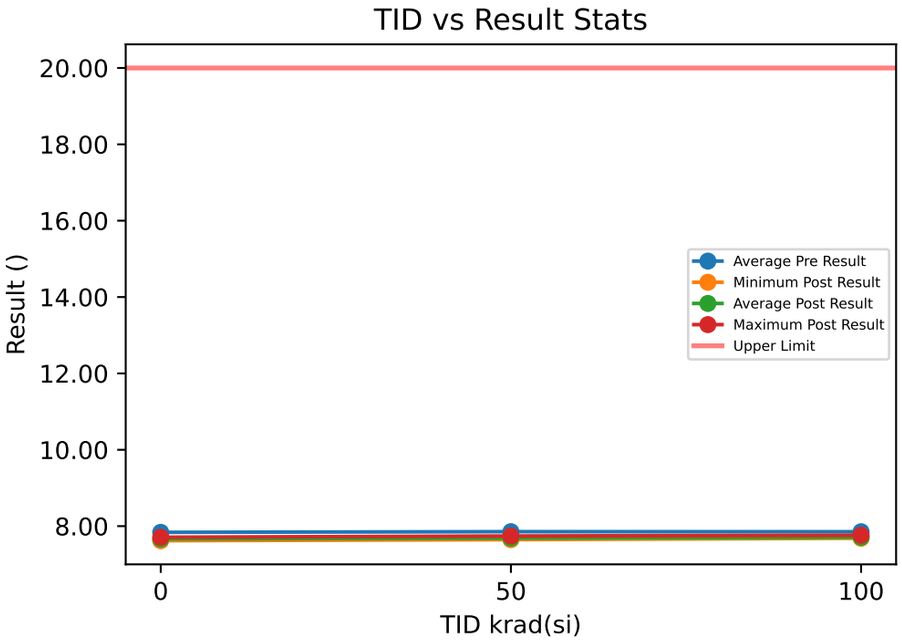
Test Results (Upper Limit = 20.0 ())

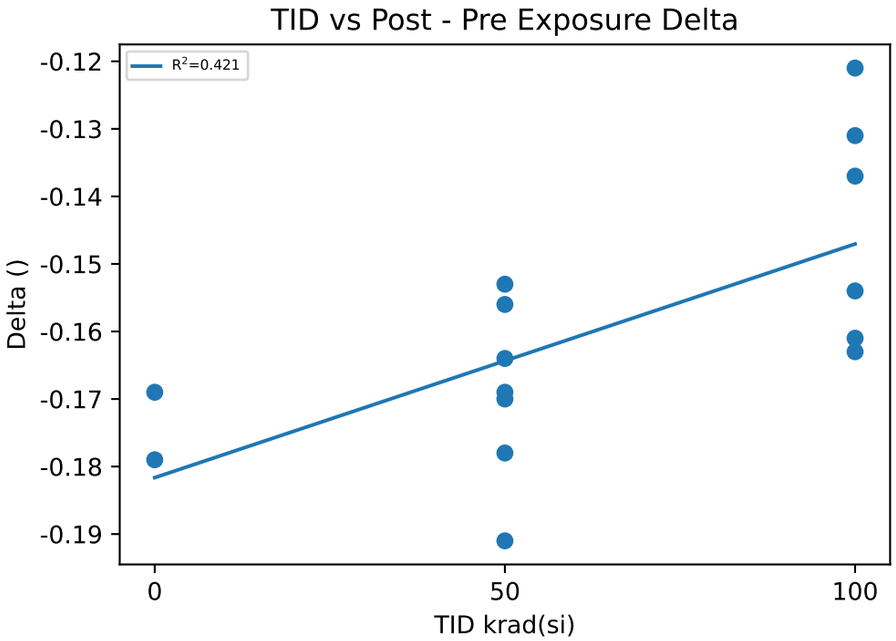
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	7.774	7.833	0.059
89	50	Biased	7.758	7.831	0.073
90	50	Biased	7.735	7.795	0.06
92	50	Biased	7.794	7.878	0.084
93	50	Unbiased	7.731	7.802	0.071
94	50	Unbiased	7.762	7.821	0.059
95	50	Unbiased	7.658	7.756	0.098
96	100	Biased	7.844	7.901	0.057
97	100	Biased	7.715	7.788	0.073
98	100	Biased	7.695	7.792	0.097
99	100	Unbiased	7.708	7.823	0.115
100	100	Unbiased	7.758	7.845	0.087
101	100	Unbiased	7.724	7.828	0.104
102	0	Correlation	7.66	7.723	0.063
103	0	Correlation	7.767	7.84	0.073

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.66	7.7135	7.767	0.07566	7.723	7.7815	7.84	0.082731	0.063	0.068	0.073	0.0070711
50	7.658	7.7446	7.794	0.043901	7.756	7.8166	7.878	0.037898	0.059	0.072	0.098	0.014742
100	7.695	7.7407	7.844	0.054895	7.788	7.8295	7.901	0.041293	0.057	0.088833	0.115	0.021208

Device Test: 18.13 RESET_RPMOS_HIGH_V(Res_PU_RESETB2/RESETB2/7/3/0/0/2/@RESET_RPMOS_HIGH_V)





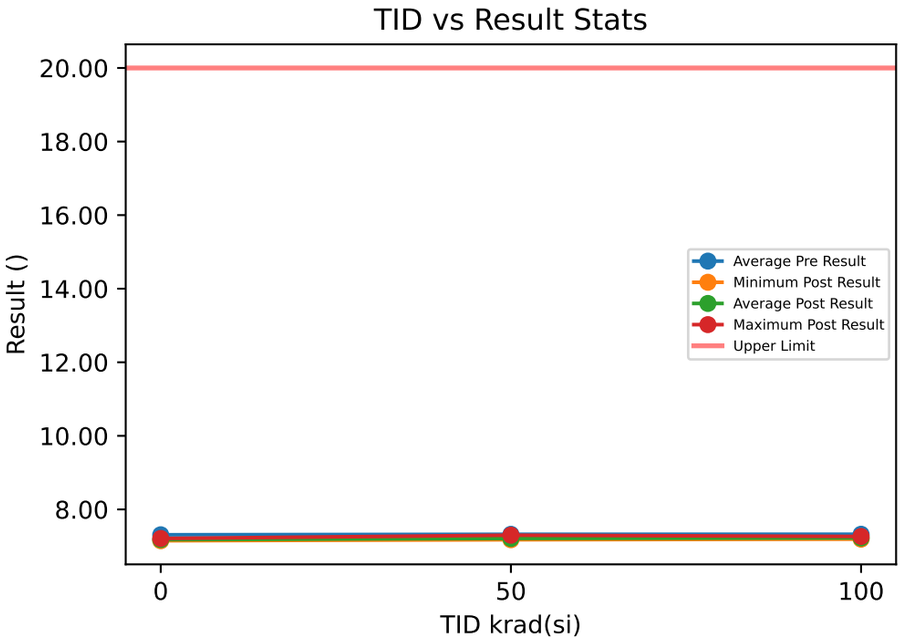
Test Results (Upper Limit = 20.0 ())

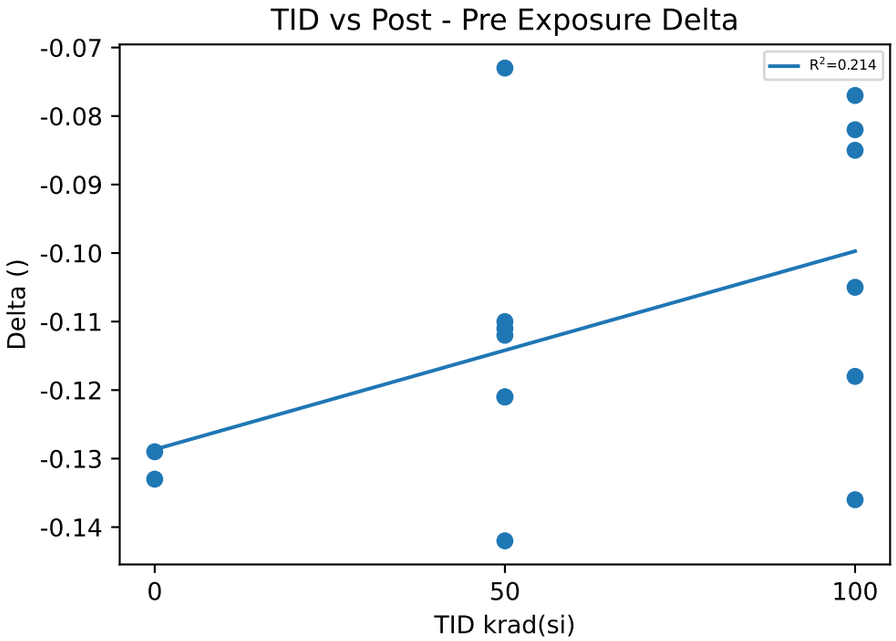
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	7.834	7.665	-0.169
89	50	Biased	7.847	7.677	-0.17
90	50	Biased	7.87	7.679	-0.191
92	50	Biased	7.894	7.741	-0.153
93	50	Unbiased	7.863	7.707	-0.156
94	50	Unbiased	7.868	7.69	-0.178
95	50	Unbiased	7.81	7.646	-0.164
96	100	Biased	7.916	7.762	-0.154
97	100	Biased	7.862	7.701	-0.161
98	100	Biased	7.83	7.693	-0.137
99	100	Unbiased	7.833	7.702	-0.131
100	100	Unbiased	7.876	7.713	-0.163
101	100	Unbiased	7.804	7.683	-0.121
102	0	Correlation	7.787	7.618	-0.169
103	0	Correlation	7.888	7.709	-0.179

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.787	7.8375	7.888	0.071418	7.618	7.6635	7.709	0.064347	-0.179	-0.174	-0.169	0.0070711
50	7.81	7.8551	7.894	0.027413	7.646	7.6864	7.741	0.030691	-0.191	-0.16871	-0.153	0.013009
100	7.804	7.8535	7.916	0.039768	7.683	7.709	7.762	0.027821	-0.163	-0.1445	-0.121	0.017295

Device Test: 18.14 RESET_RPMOS_HIGH_V(Res_PU_RESETB3/RESETB3/7/3/0/0/2/@RESET_RPMOS_HIGH_V)





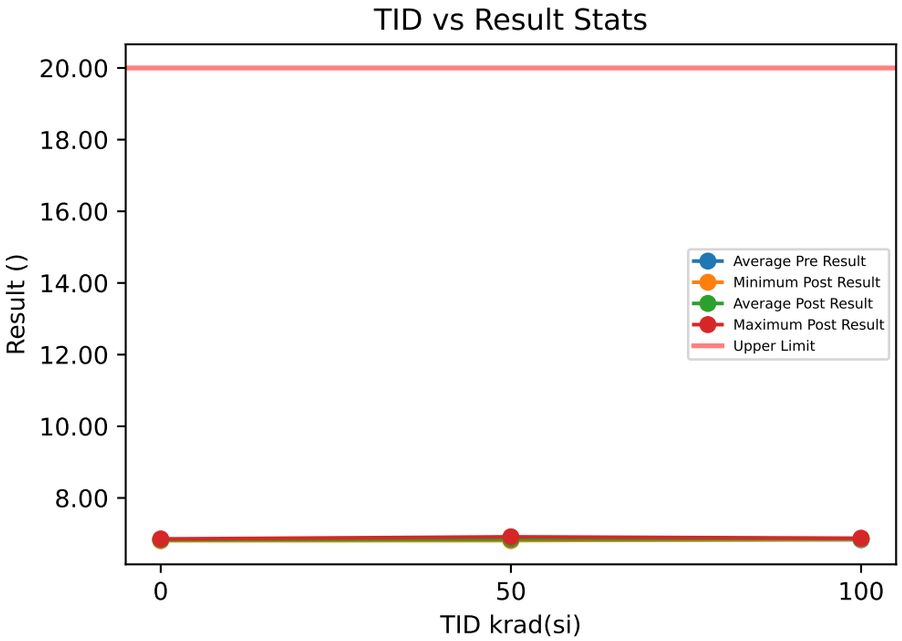
Test Results (Upper Limit = 20.0 ())

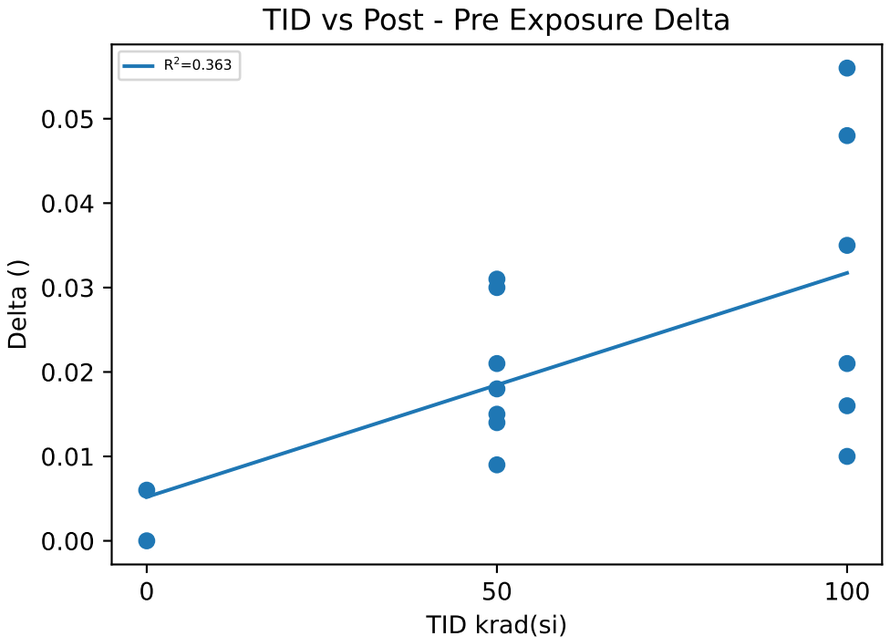
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	7.289	7.178	-0.111
89	50	Biased	7.308	7.196	-0.112
90	50	Biased	7.318	7.176	-0.142
92	50	Biased	7.372	7.299	-0.073
93	50	Unbiased	7.328	7.218	-0.11
94	50	Unbiased	7.33	7.209	-0.121
95	50	Unbiased	7.318	7.197	-0.121
96	100	Biased	7.37	7.265	-0.105
97	100	Biased	7.359	7.223	-0.136
98	100	Biased	7.277	7.192	-0.085
99	100	Unbiased	7.277	7.2	-0.077
100	100	Unbiased	7.339	7.221	-0.118
101	100	Unbiased	7.327	7.245	-0.082
102	0	Correlation	7.278	7.149	-0.129
103	0	Correlation	7.343	7.21	-0.133

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.278	7.3105	7.343	0.045962	7.149	7.1795	7.21	0.043134	-0.133	-0.131	-0.129	0.0028284
50	7.289	7.3233	7.372	0.025513	7.176	7.2104	7.299	0.041892	-0.142	-0.11286	-0.073	0.020748
100	7.277	7.3248	7.37	0.039972	7.192	7.2243	7.265	0.027318	-0.136	-0.1005	-0.077	0.02333

Device Test: 18.15 RESET_RPMOS_HIGH_V(Res_PU_RESETB4/RESETB4/7/3/0/0/2/@RESET_RPMOS_HIGH_V)





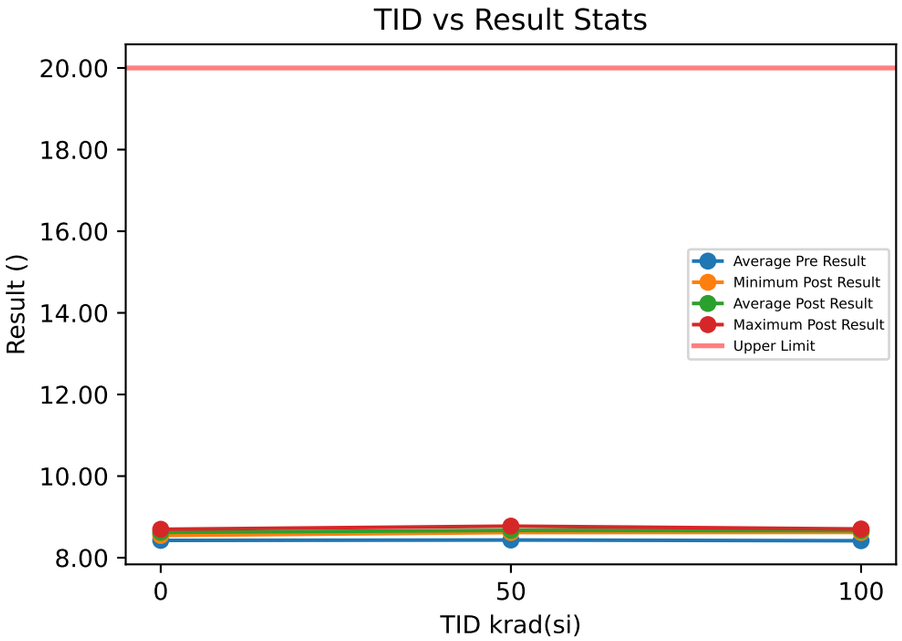
Test Results (Upper Limit = 20.0 ())

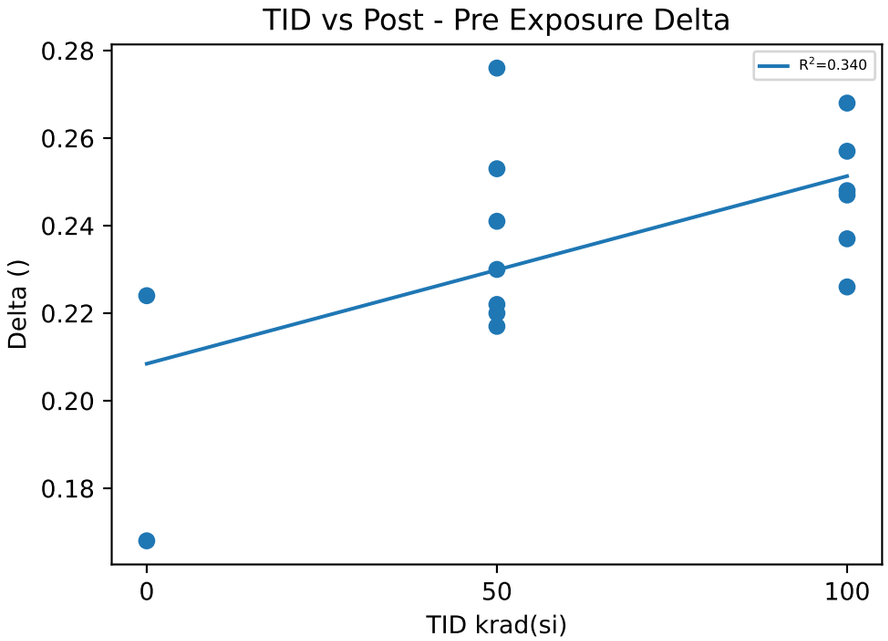
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	6.821	6.835	0.014
89	50	Biased	6.808	6.829	0.021
90	50	Biased	6.8	6.809	0.009
92	50	Biased	6.885	6.915	0.03
93	50	Unbiased	6.847	6.862	0.015
94	50	Unbiased	6.826	6.844	0.018
95	50	Unbiased	6.799	6.83	0.031
96	100	Biased	6.86	6.876	0.016
97	100	Biased	6.826	6.847	0.021
98	100	Biased	6.812	6.847	0.035
99	100	Unbiased	6.821	6.869	0.048
100	100	Unbiased	6.859	6.869	0.01
101	100	Unbiased	6.819	6.875	0.056
102	0	Correlation	6.8	6.806	0.006
103	0	Correlation	6.856	6.856	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.8	6.828	6.856	0.039598	6.806	6.831	6.856	0.035355	0	0.003	0.006	0.0042426
50	6.799	6.8266	6.885	0.030751	6.809	6.8463	6.915	0.034291	0.009	0.019714	0.031	0.0082404
100	6.812	6.8328	6.86	0.021142	6.847	6.8638	6.876	0.013363	0.01	0.031	0.056	0.018417

Device Test: 18.16 PWRGD_RPMOS_HIGH_V(Res_PU_PWRDG/PWRGD/7/3/0/0/2/@PWRGD_RPMOS_HIGH_V)





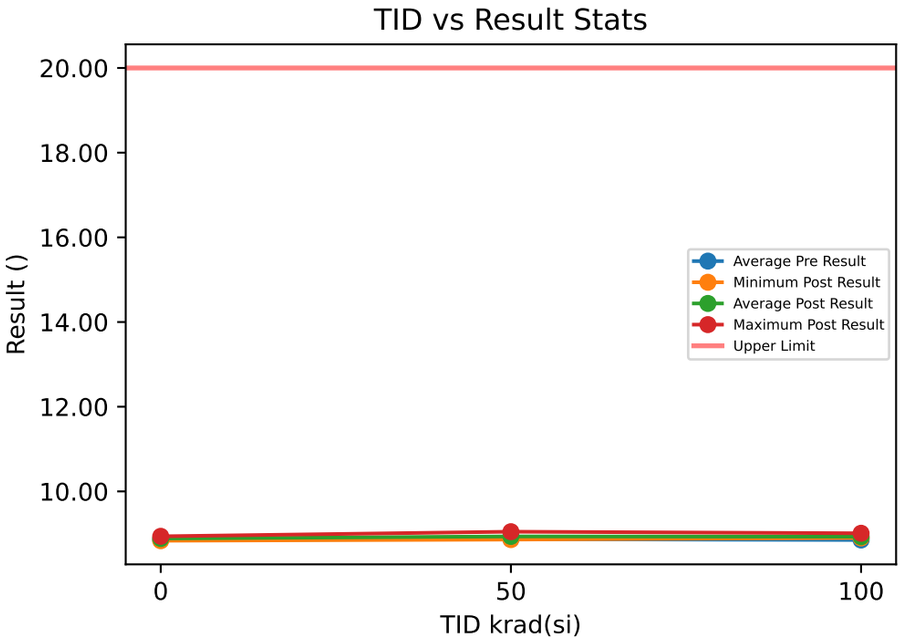
Test Results (Upper Limit = 20.0 ())

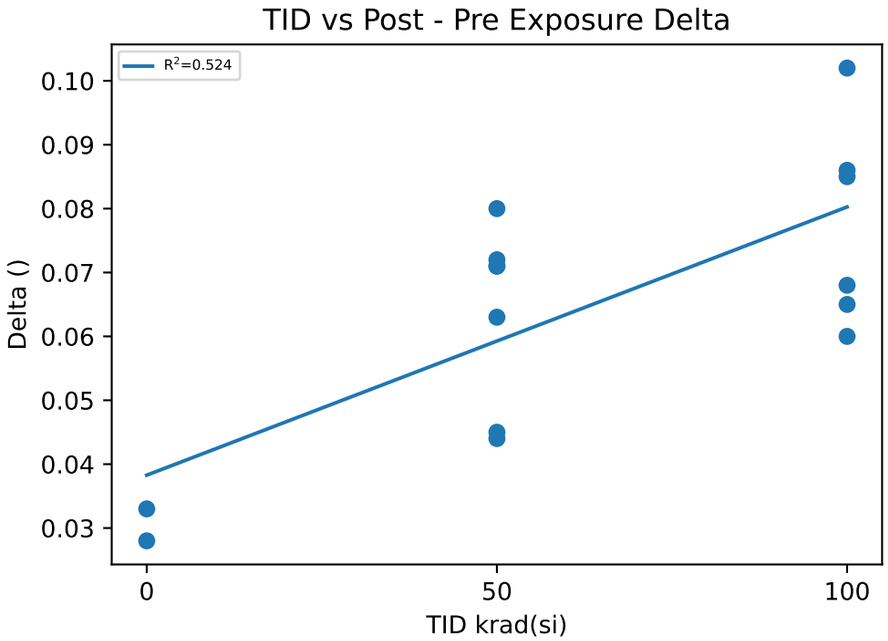
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	8.4	8.617	0.217
89	50	Biased	8.422	8.644	0.222
90	50	Biased	8.411	8.641	0.23
92	50	Biased	8.498	8.774	0.276
93	50	Unbiased	8.438	8.691	0.253
94	50	Unbiased	8.426	8.646	0.22
95	50	Unbiased	8.442	8.683	0.241
96	100	Biased	8.457	8.704	0.247
97	100	Biased	8.412	8.66	0.248
98	100	Biased	8.416	8.684	0.268
99	100	Unbiased	8.394	8.62	0.226
100	100	Unbiased	8.394	8.631	0.237
101	100	Unbiased	8.427	8.684	0.257
102	0	Correlation	8.377	8.545	0.168
103	0	Correlation	8.473	8.697	0.224

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.377	8.425	8.473	0.067882	8.545	8.621	8.697	0.10748	0.168	0.196	0.224	0.039598
50	8.4	8.4339	8.498	0.031804	8.617	8.6709	8.774	0.052158	0.217	0.237	0.276	0.021432
100	8.394	8.4167	8.457	0.023594	8.62	8.6638	8.704	0.032987	0.226	0.24717	0.268	0.014716

Device Test: 18.17 WDO_RPMOS_HIGH_V(Res_PU_WDOB/WDOB/7/3/0/0/2/@WDO_RPMOS_HIGH_V)





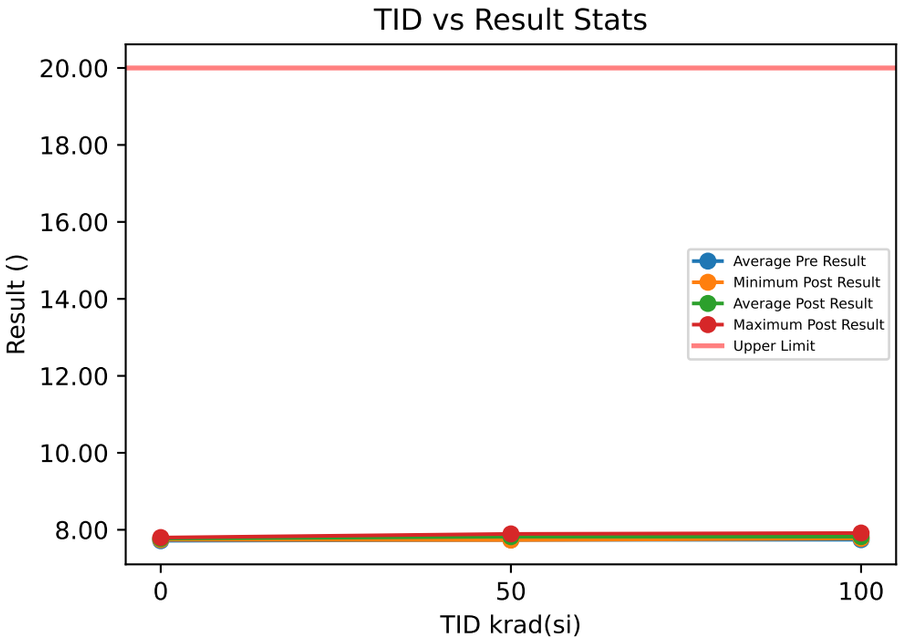
Test Results (Upper Limit = 20.0 ())

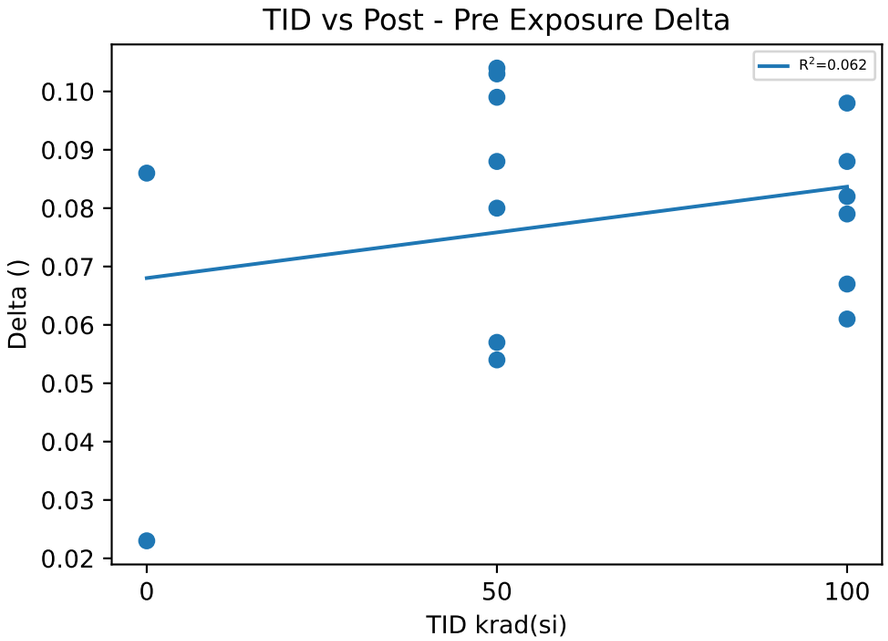
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	8.818	8.862	0.044
89	50	Biased	8.88	8.925	0.045
90	50	Biased	8.853	8.924	0.071
92	50	Biased	8.968	9.048	0.08
93	50	Unbiased	8.868	8.939	0.071
94	50	Unbiased	8.874	8.946	0.072
95	50	Unbiased	8.849	8.912	0.063
96	100	Biased	8.946	9.011	0.065
97	100	Biased	8.871	8.939	0.068
98	100	Biased	8.8	8.902	0.102
99	100	Unbiased	8.826	8.912	0.086
100	100	Unbiased	8.847	8.907	0.06
101	100	Unbiased	8.822	8.907	0.085
102	0	Correlation	8.807	8.835	0.028
103	0	Correlation	8.906	8.939	0.033

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.807	8.8565	8.906	0.070004	8.835	8.887	8.939	0.073539	0.028	0.0305	0.033	0.0035355
50	8.818	8.8729	8.968	0.046728	8.862	8.9366	9.048	0.056225	0.044	0.063714	0.08	0.01402
100	8.8	8.852	8.946	0.051965	8.902	8.9297	9.011	0.04197	0.06	0.077667	0.102	0.016008

Device Test: 18.18 RESET_RPMOS_HIGH_V(Res_PU_RESETB1/RESETB1/7/14/0/0/2/@RESET_RPMOS_HIGH_V)





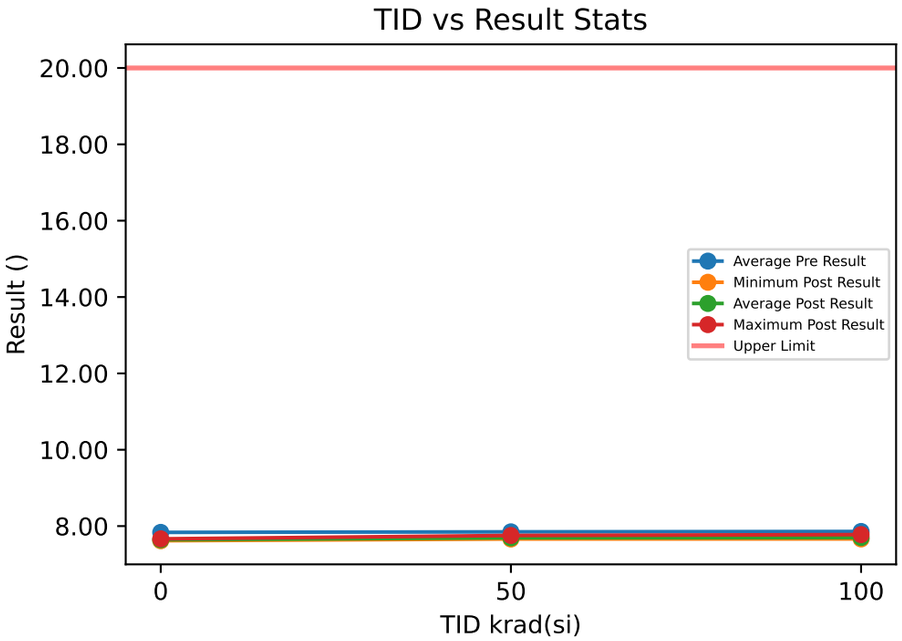
Test Results (Upper Limit = 20.0 ())

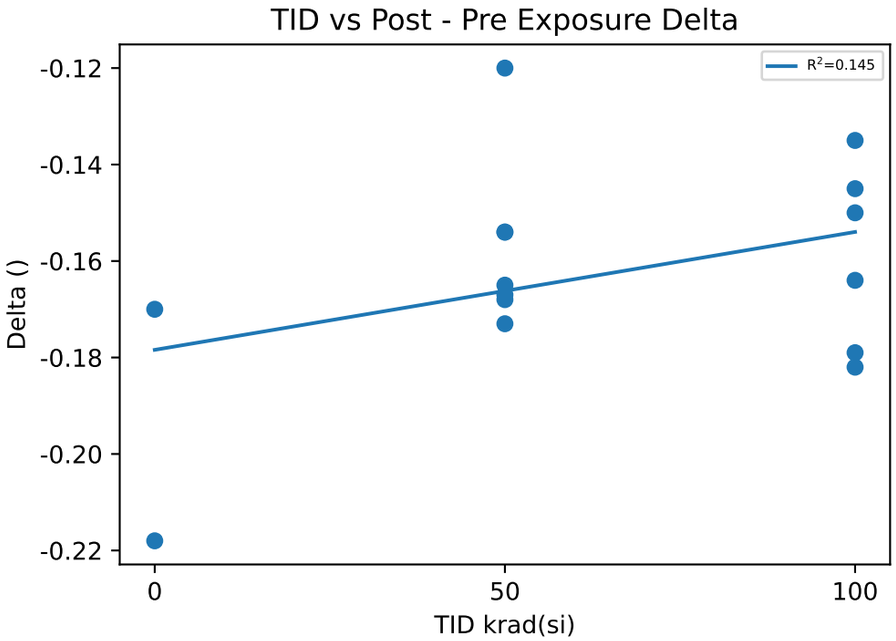
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	7.743	7.831	0.088
89	50	Biased	7.753	7.833	0.08
90	50	Biased	7.73	7.784	0.054
92	50	Biased	7.789	7.893	0.104
93	50	Unbiased	7.726	7.825	0.099
94	50	Unbiased	7.745	7.848	0.103
95	50	Unbiased	7.676	7.733	0.057
96	100	Biased	7.837	7.916	0.079
97	100	Biased	7.706	7.804	0.098
98	100	Biased	7.707	7.774	0.067
99	100	Unbiased	7.709	7.791	0.082
100	100	Unbiased	7.775	7.836	0.061
101	100	Unbiased	7.723	7.811	0.088
102	0	Correlation	7.657	7.743	0.086
103	0	Correlation	7.775	7.798	0.023

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.657	7.716	7.775	0.083439	7.743	7.7705	7.798	0.038891	0.023	0.0545	0.086	0.044548
50	7.676	7.7374	7.789	0.034034	7.733	7.821	7.893	0.050474	0.054	0.083571	0.104	0.020999
100	7.706	7.7428	7.837	0.053068	7.774	7.822	7.916	0.050482	0.061	0.079167	0.098	0.013556

Device Test: 18.19 RESET_RPMOS_HIGH_V(Res_PU_RESETB2/RESETB2/7/14/0/0/2/@RESET_RPMOS_HIGH_V)





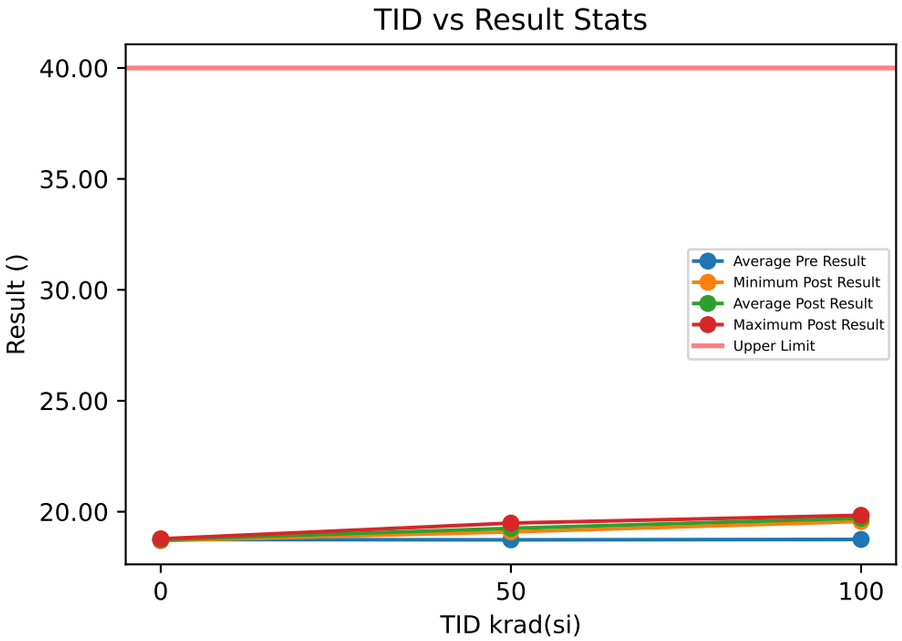
Test Results (Upper Limit = 20.0 ())

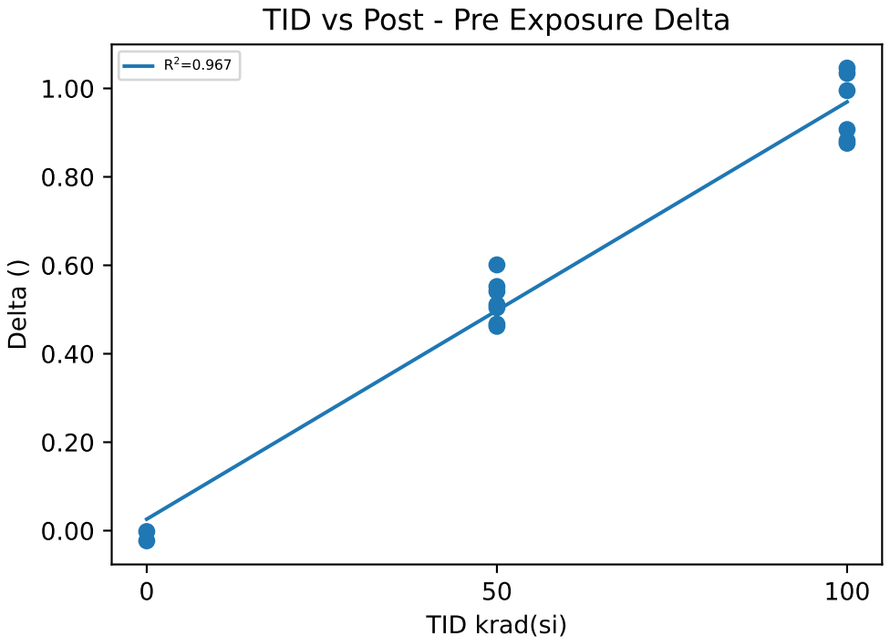
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	7.837	7.67	-0.167
89	50	Biased	7.842	7.669	-0.173
90	50	Biased	7.856	7.688	-0.168
92	50	Biased	7.874	7.754	-0.12
93	50	Unbiased	7.866	7.701	-0.165
94	50	Unbiased	7.855	7.701	-0.154
95	50	Unbiased	7.816	7.662	-0.154
96	100	Biased	7.912	7.777	-0.135
97	100	Biased	7.859	7.709	-0.15
98	100	Biased	7.833	7.669	-0.164
99	100	Unbiased	7.846	7.664	-0.182
100	100	Unbiased	7.888	7.709	-0.179
101	100	Unbiased	7.817	7.672	-0.145
102	0	Correlation	7.787	7.617	-0.17
103	0	Correlation	7.884	7.666	-0.218

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.787	7.8355	7.884	0.068589	7.617	7.6415	7.666	0.034648	-0.218	-0.194	-0.17	0.033941
50	7.816	7.8494	7.874	0.019492	7.662	7.6921	7.754	0.031451	-0.173	-0.15729	-0.12	0.017923
100	7.817	7.8592	7.912	0.03538	7.664	7.7	7.777	0.042736	-0.182	-0.15917	-0.135	0.01901

Device Test: 18.2 RESET_RPMOS_LOW_V(Res_PU_RESETB3/RESETB3/1.6/3/0/0/2/@RESET_RPMOS_LOW_V)





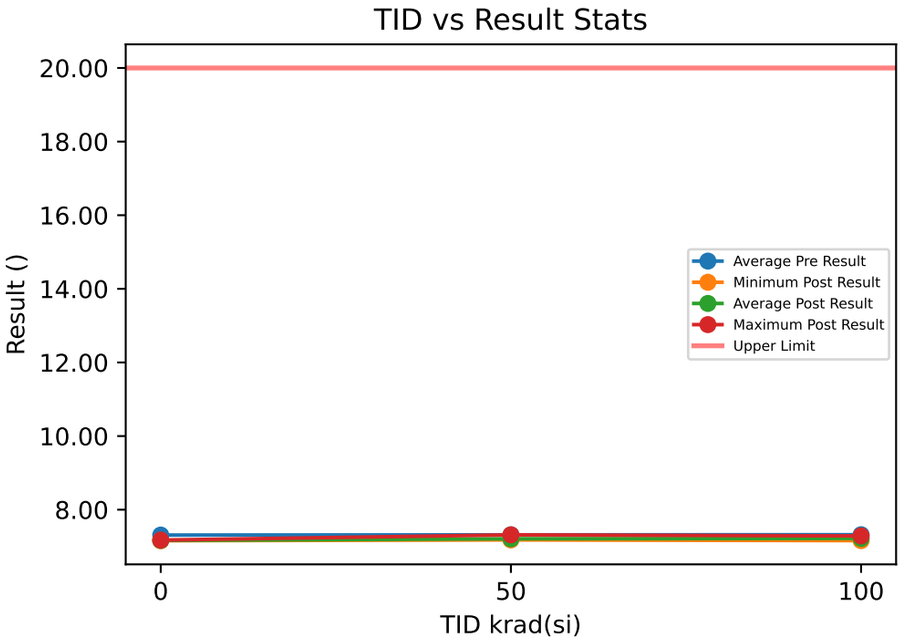
Test Results (Upper Limit = 40.0 ())

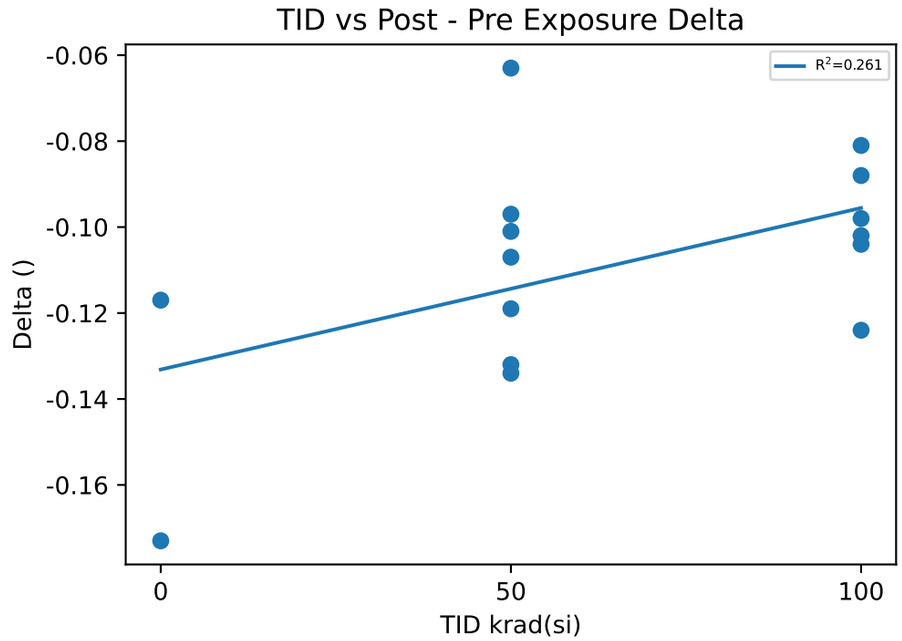
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	18.71	19.221	0.511
89	50	Biased	18.54	19.092	0.552
90	50	Biased	18.723	19.264	0.541
92	50	Biased	18.886	19.487	0.601
93	50	Unbiased	18.841	19.345	0.504
94	50	Unbiased	18.629	19.091	0.462
95	50	Unbiased	18.799	19.266	0.467
96	100	Biased	18.702	19.736	1.034
97	100	Biased	18.792	19.838	1.046
98	100	Biased	18.688	19.683	0.995
99	100	Unbiased	18.684	19.56	0.876
100	100	Unbiased	18.796	19.678	0.882
101	100	Unbiased	18.845	19.752	0.907
102	0	Correlation	18.716	18.693	-0.023
103	0	Correlation	18.78	18.778	-0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.716	18.748	18.78	0.045255	18.693	18.736	18.778	0.060104	-0.023	-0.0125	-0.002	0.014849
50	18.54	18.733	18.886	0.12119	19.091	19.252	19.487	0.13946	0.462	0.51971	0.601	0.04922
100	18.684	18.751	18.845	0.068412	19.56	19.708	19.838	0.092789	0.876	0.95667	1.046	0.077433

Device Test: 18.20 RESET_RPMOS_HIGH_V(Res_PU_RESETB3/RESETB3/7/14/0/0/2/@RESET_RPMOS_HIGH_V)





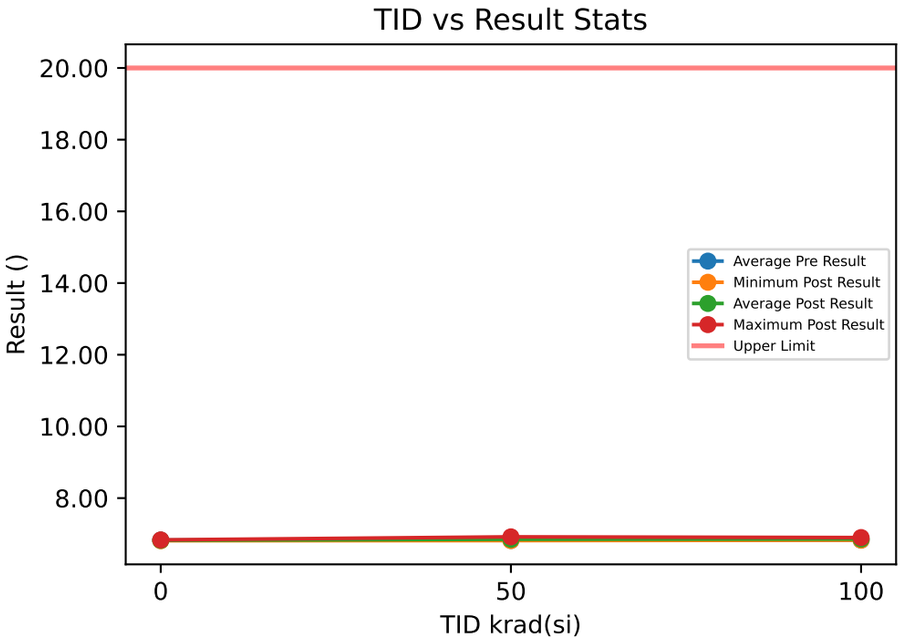
Test Results (Upper Limit = 20.0 ())

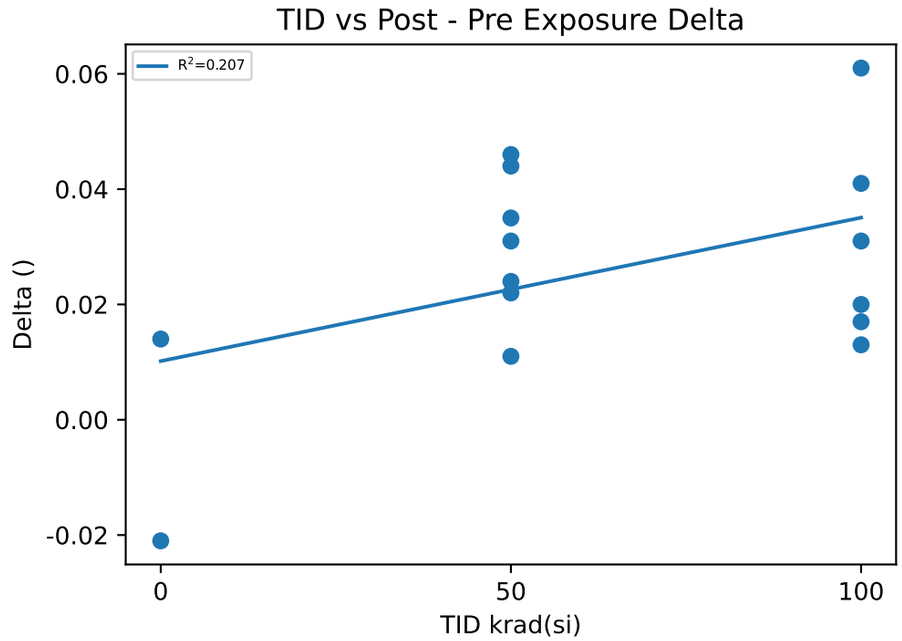
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	7.28	7.179	-0.101
89	50	Biased	7.306	7.187	-0.119
90	50	Biased	7.311	7.179	-0.132
92	50	Biased	7.379	7.316	-0.063
93	50	Unbiased	7.322	7.215	-0.107
94	50	Unbiased	7.304	7.207	-0.097
95	50	Unbiased	7.313	7.179	-0.134
96	100	Biased	7.375	7.287	-0.088
97	100	Biased	7.33	7.249	-0.081
98	100	Biased	7.284	7.16	-0.124
99	100	Unbiased	7.273	7.169	-0.104
100	100	Unbiased	7.333	7.231	-0.102
101	100	Unbiased	7.325	7.227	-0.098
102	0	Correlation	7.274	7.157	-0.117
103	0	Correlation	7.347	7.174	-0.173

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.274	7.3105	7.347	0.051619	7.157	7.1655	7.174	0.012021	-0.173	-0.145	-0.117	0.039598
50	7.28	7.3164	7.379	0.03049	7.179	7.2089	7.316	0.049452	-0.134	-0.10757	-0.063	0.024385
100	7.273	7.32	7.375	0.036943	7.16	7.2205	7.287	0.048373	-0.124	-0.0995	-0.081	0.014856

Device Test: 18.21 RESET_RPMOS_HIGH_V(Res_PU_RESETB4/RESETB4/7/14/0/0/2/@RESET_RPMOS_HIGH_V)





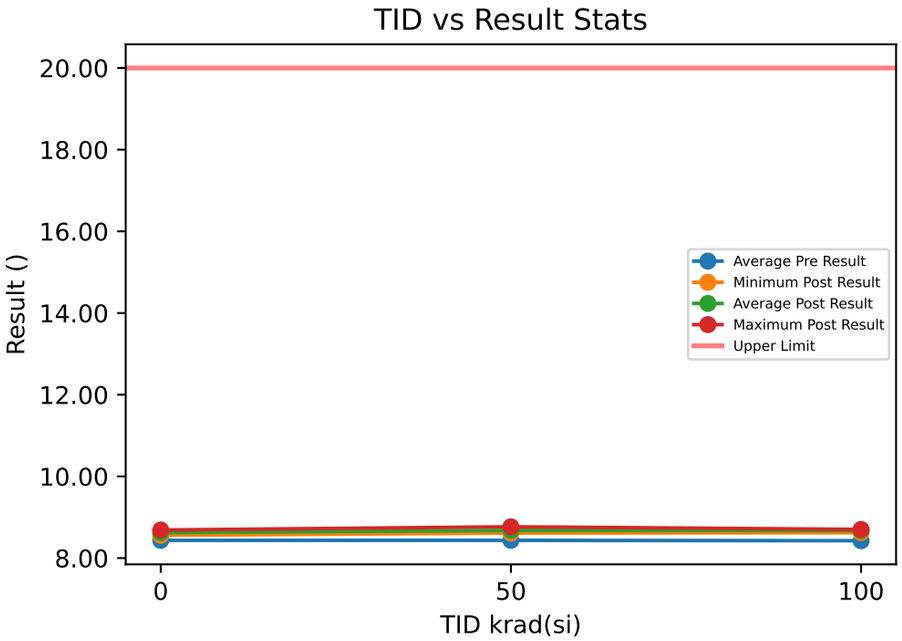
Test Results (Upper Limit = 20.0 ())

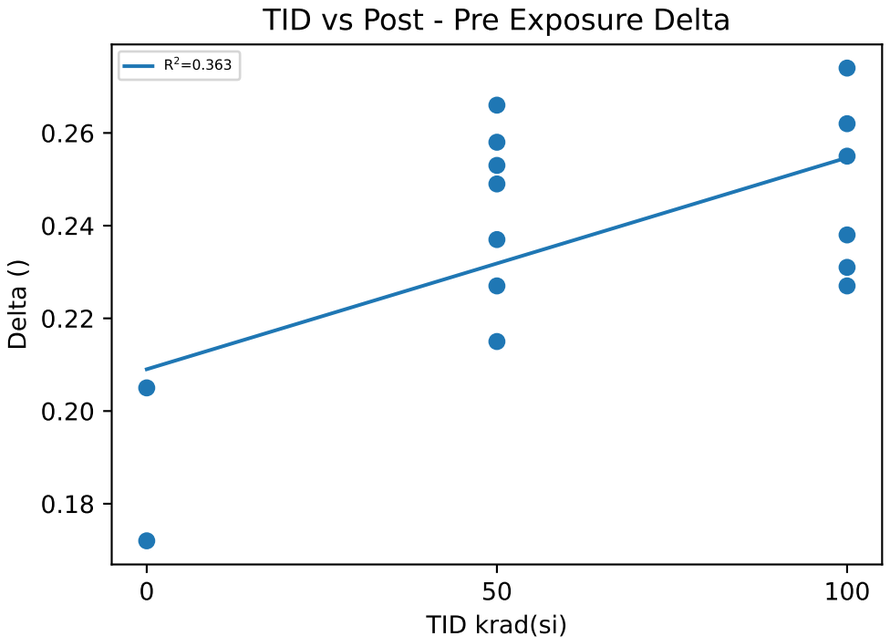
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	6.806	6.852	0.046
89	50	Biased	6.811	6.833	0.022
90	50	Biased	6.812	6.823	0.011
92	50	Biased	6.875	6.919	0.044
93	50	Unbiased	6.835	6.866	0.031
94	50	Unbiased	6.813	6.848	0.035
95	50	Unbiased	6.791	6.815	0.024
96	100	Biased	6.838	6.899	0.061
97	100	Biased	6.823	6.864	0.041
98	100	Biased	6.806	6.826	0.02
99	100	Unbiased	6.81	6.827	0.017
100	100	Unbiased	6.858	6.871	0.013
101	100	Unbiased	6.836	6.867	0.031
102	0	Correlation	6.797	6.811	0.014
103	0	Correlation	6.855	6.834	-0.021

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.797	6.826	6.855	0.041012	6.811	6.8225	6.834	0.016263	-0.021	-0.0035	0.014	0.024749
50	6.791	6.8204	6.875	0.027324	6.815	6.8509	6.919	0.034792	0.011	0.030429	0.046	0.012501
100	6.806	6.8285	6.858	0.01947	6.826	6.859	6.899	0.028093	0.013	0.0305	0.061	0.018108

Device Test: 18.22 PWRGD_RPMOS_HIGH_V(Res_PU_PWRDG/PWRGD/7/14/0/0/2/@PWRGD_RPMOS_HIGH_V)





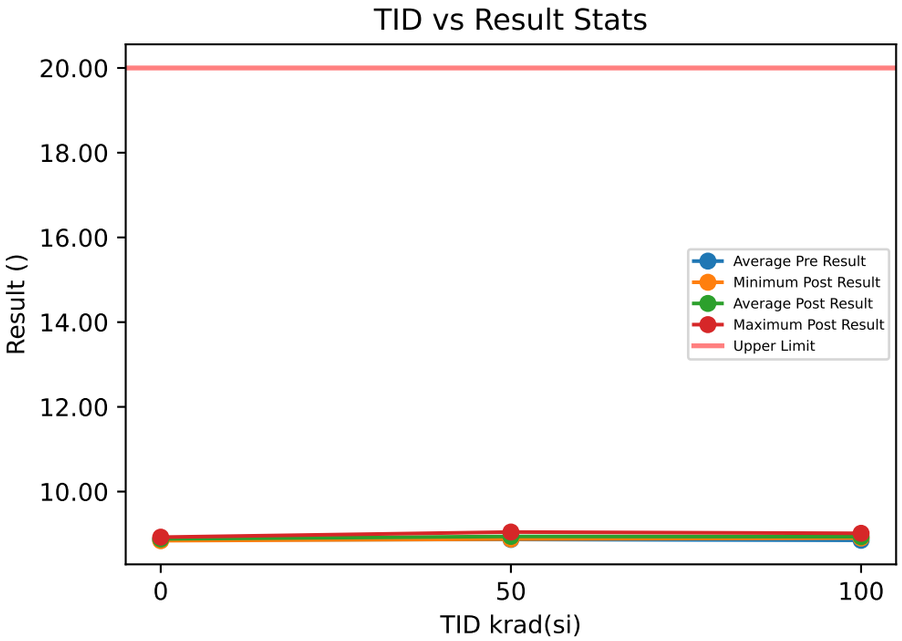
Test Results (Upper Limit = 20.0 ())

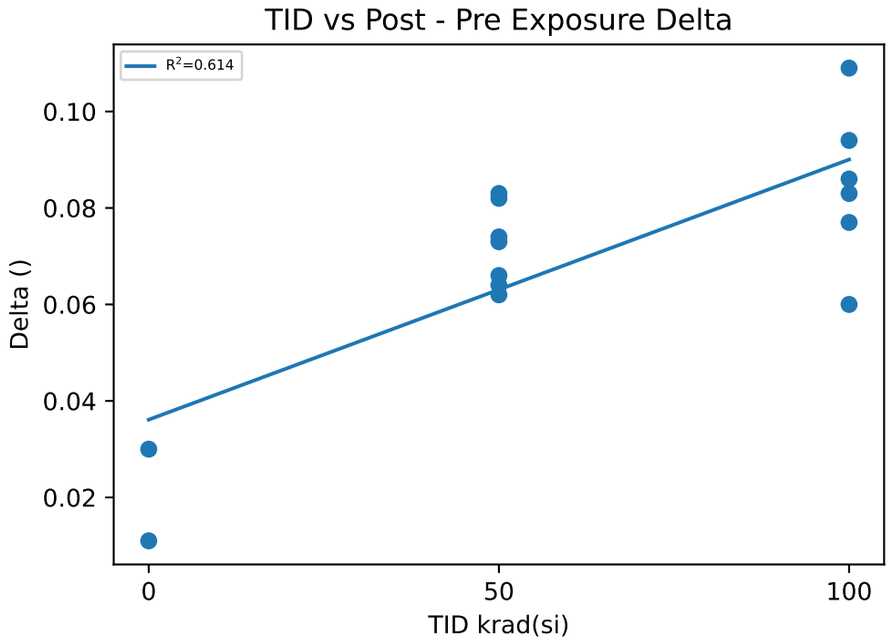
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	8.398	8.613	0.215
89	50	Biased	8.435	8.672	0.237
90	50	Biased	8.411	8.638	0.227
92	50	Biased	8.5	8.766	0.266
93	50	Unbiased	8.445	8.698	0.253
94	50	Unbiased	8.413	8.671	0.258
95	50	Unbiased	8.442	8.691	0.249
96	100	Biased	8.475	8.702	0.227
97	100	Biased	8.421	8.676	0.255
98	100	Biased	8.424	8.698	0.274
99	100	Unbiased	8.383	8.621	0.238
100	100	Unbiased	8.417	8.648	0.231
101	100	Unbiased	8.431	8.693	0.262
102	0	Correlation	8.386	8.558	0.172
103	0	Correlation	8.482	8.687	0.205

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.386	8.434	8.482	0.067882	8.558	8.6225	8.687	0.091217	0.172	0.1885	0.205	0.023335
50	8.398	8.4349	8.5	0.033672	8.613	8.6784	8.766	0.048686	0.215	0.24357	0.266	0.018091
100	8.383	8.4252	8.475	0.0296	8.621	8.673	8.702	0.032261	0.227	0.24783	0.274	0.018713

Device Test: 18.23 WDO_RPMOS_HIGH_V(Res_PU_WDOB/WDOB/7/14/0/0/2/@WDO_RPMOS_HIGH_V)





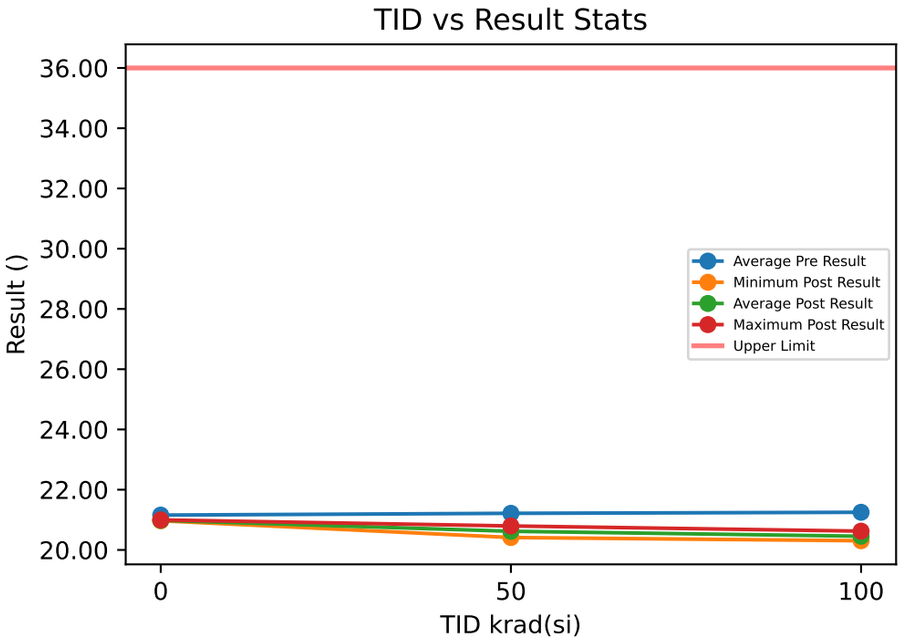
Test Results (Upper Limit = 20.0 ())

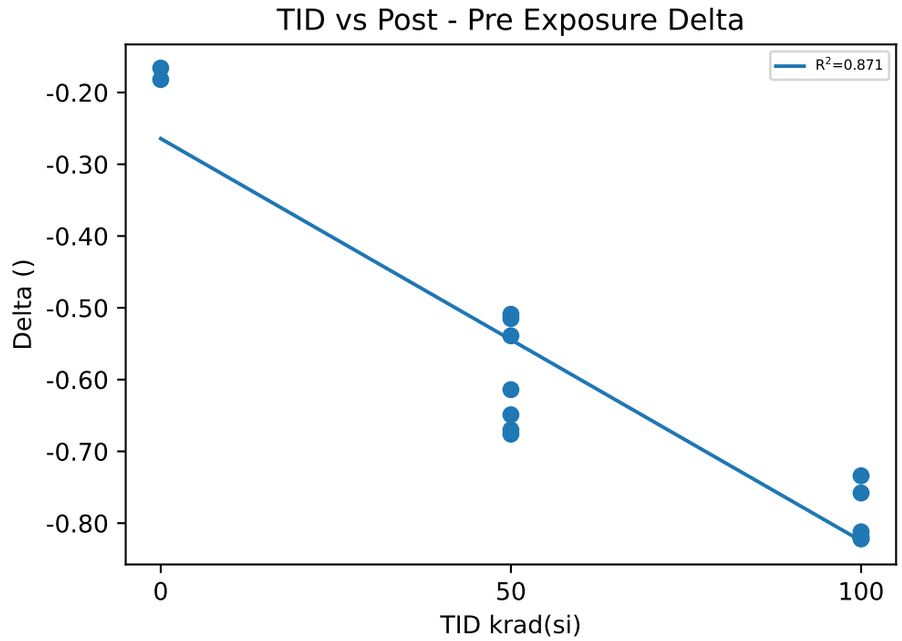
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	8.816	8.878	0.062
89	50	Biased	8.867	8.931	0.064
90	50	Biased	8.849	8.922	0.073
92	50	Biased	8.963	9.045	0.082
93	50	Unbiased	8.858	8.941	0.083
94	50	Unbiased	8.878	8.952	0.074
95	50	Unbiased	8.858	8.924	0.066
96	100	Biased	8.955	9.015	0.06
97	100	Biased	8.865	8.951	0.086
98	100	Biased	8.8	8.909	0.109
99	100	Unbiased	8.821	8.904	0.083
100	100	Unbiased	8.845	8.922	0.077
101	100	Unbiased	8.812	8.906	0.094
102	0	Correlation	8.81	8.84	0.03
103	0	Correlation	8.913	8.924	0.011

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.81	8.8615	8.913	0.072832	8.84	8.882	8.924	0.059397	0.011	0.0205	0.03	0.013435
50	8.816	8.8699	8.963	0.0454	8.878	8.9419	9.045	0.051073	0.062	0.072	0.083	0.0084261
100	8.8	8.8497	8.955	0.056673	8.904	8.9345	9.015	0.043131	0.06	0.084833	0.109	0.016437

Device Test: 18.24 RESET_RNMOS(Res_PD_RESETB1/RESETB1/1.6/3/0/0/2/@RESET_RNMOS)





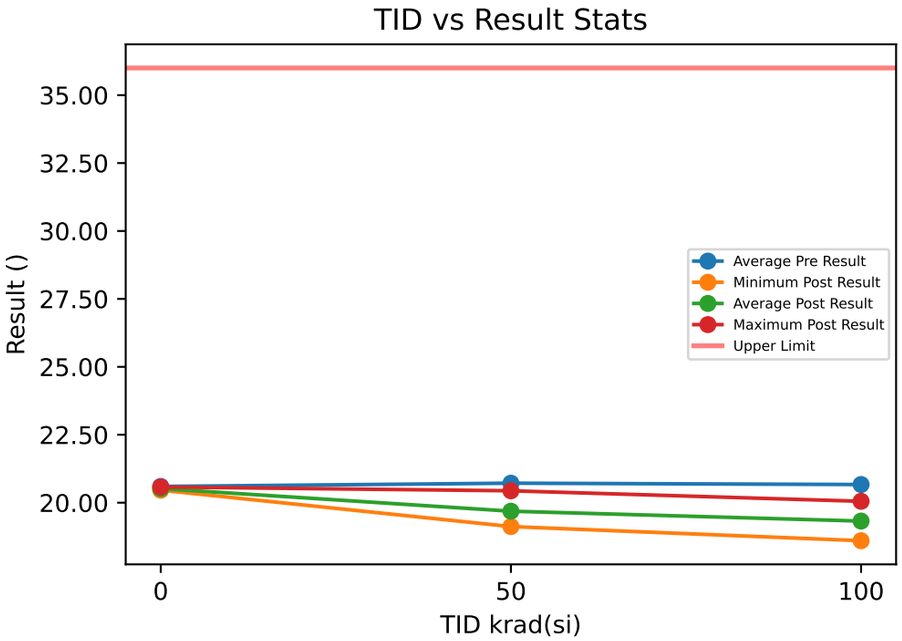
Test Results (Upper Limit = 36.0 ())

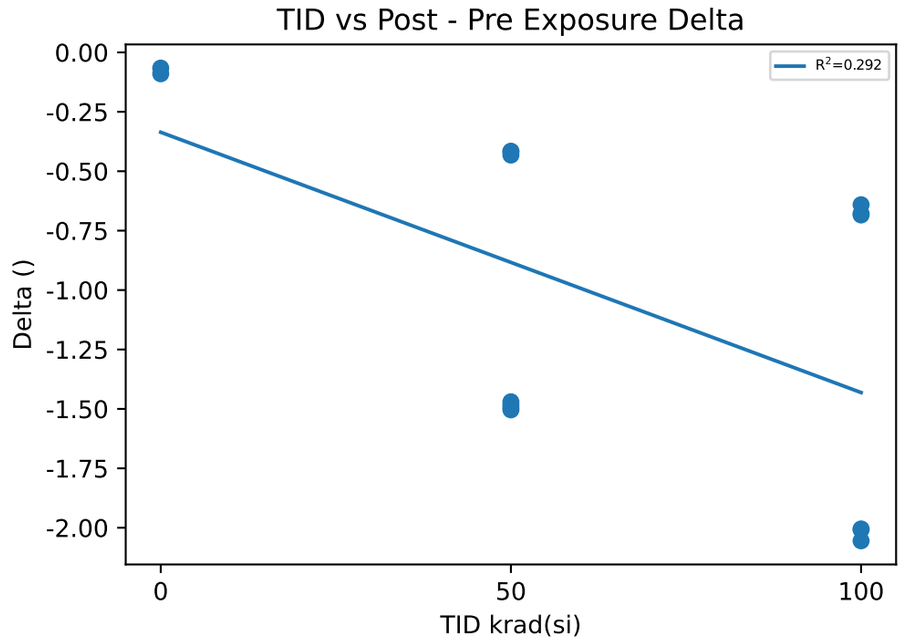
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	21.083	20.413	-0.67
89	50	Biased	21.227	20.578	-0.649
90	50	Biased	21.293	20.617	-0.676
92	50	Biased	21.114	20.5	-0.614
93	50	Unbiased	21.257	20.748	-0.509
94	50	Unbiased	21.335	20.796	-0.539
95	50	Unbiased	21.2	20.685	-0.515
96	100	Biased	21.345	20.525	-0.82
97	100	Biased	21.127	20.306	-0.821
98	100	Biased	21.146	20.334	-0.812
99	100	Unbiased	21.446	20.624	-0.822
100	100	Unbiased	21.2	20.442	-0.758
101	100	Unbiased	21.234	20.5	-0.734
102	0	Correlation	21.134	20.968	-0.166
103	0	Correlation	21.179	20.997	-0.182

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.134	21.157	21.179	0.03182	20.968	20.983	20.997	0.020506	-0.182	-0.174	-0.166	0.011314
50	21.083	21.216	21.335	0.091506	20.413	20.62	20.796	0.13577	-0.676	-0.596	-0.509	0.073471
100	21.127	21.25	21.446	0.1234	20.306	20.455	20.624	0.12041	-0.822	-0.7945	-0.734	0.03849

Device Test: 18.25 RESET_RNMOS(Res_PD_RESETB2/RESETB2/1.6/3/0/0/2/@RESET_RNMOS)





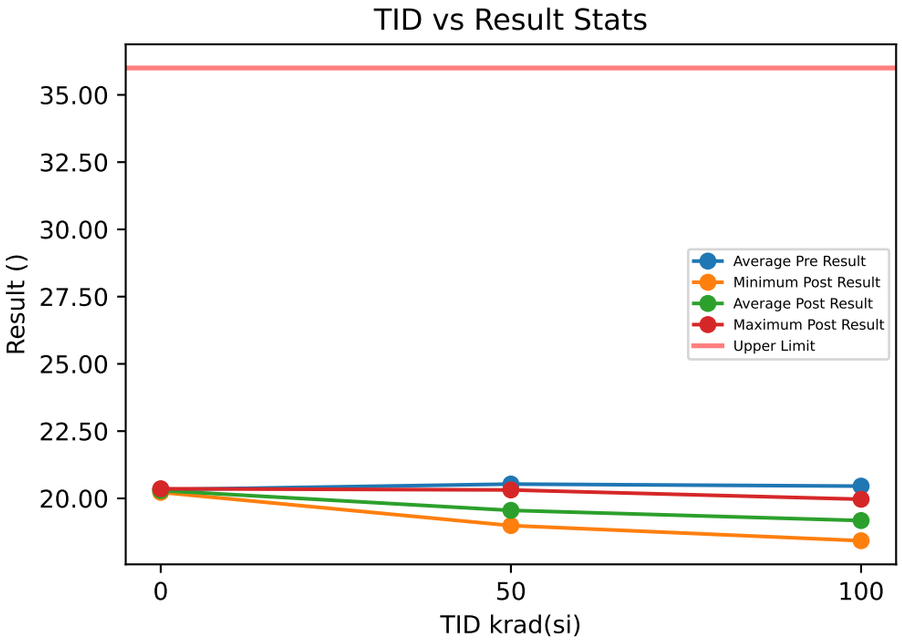
Test Results (Upper Limit = 36.0 ())

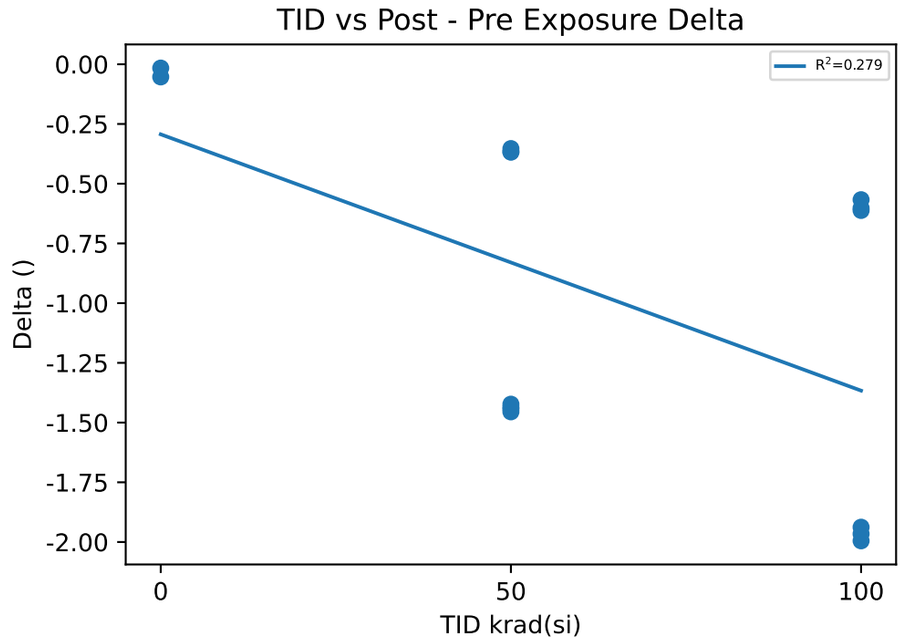
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	20.616	19.121	-1.495
89	50	Biased	20.687	19.217	-1.47
90	50	Biased	20.664	19.181	-1.483
92	50	Biased	20.927	19.423	-1.504
93	50	Unbiased	20.664	20.248	-0.416
94	50	Unbiased	20.87	20.438	-0.432
95	50	Unbiased	20.595	20.178	-0.417
96	100	Biased	20.676	18.671	-2.005
97	100	Biased	20.71	18.655	-2.055
98	100	Biased	20.608	18.6	-2.008
99	100	Unbiased	20.735	20.051	-0.684
100	100	Unbiased	20.71	20.032	-0.678
101	100	Unbiased	20.571	19.93	-0.641
102	0	Correlation	20.527	20.461	-0.066
103	0	Correlation	20.668	20.578	-0.09

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.527	20.598	20.668	0.099702	20.461	20.52	20.578	0.082731	-0.09	-0.078	-0.066	0.016971
50	20.595	20.718	20.927	0.12852	19.121	19.687	20.438	0.57544	-1.504	-1.031	-0.416	0.5701
100	20.571	20.668	20.735	0.064945	18.6	19.323	20.051	0.74769	-2.055	-1.3452	-0.641	0.74252

Device Test: 18.26 RESET_RNMOS(Res_PD_RESETB3/RESETB3/1.6/3/0/0/2/@RESET_RNMOS)





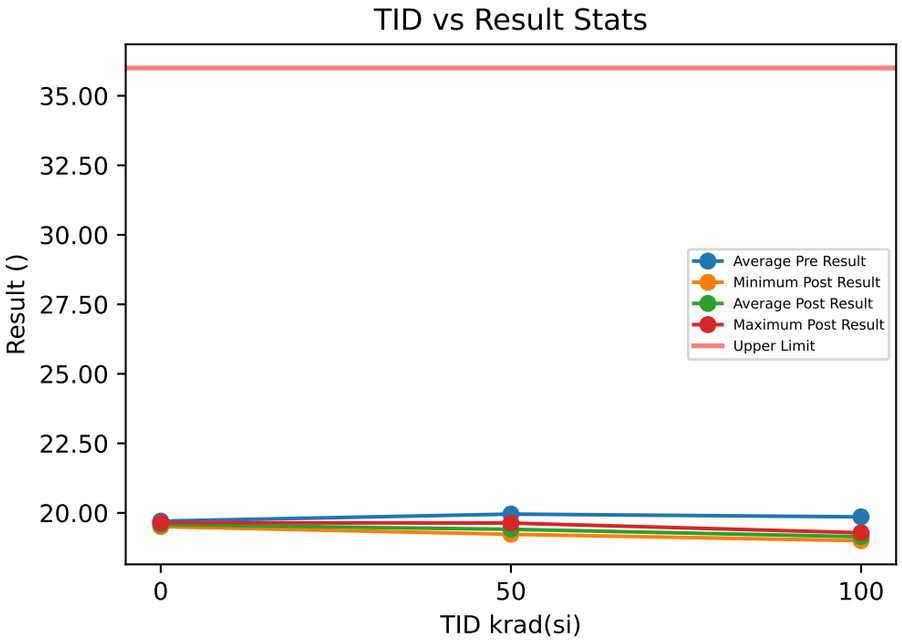
Test Results (Upper Limit = 36.0 ())

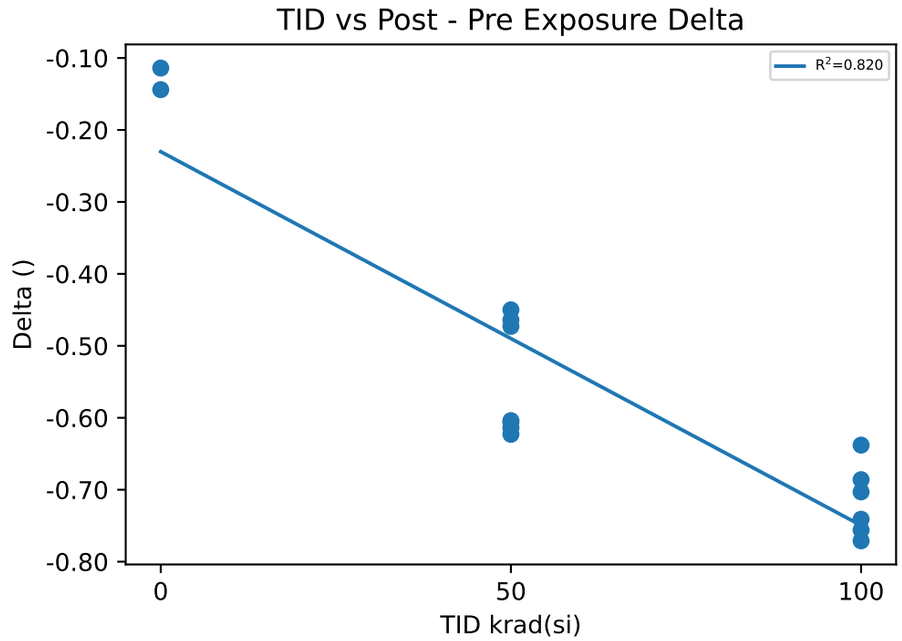
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	20.444	18.989	-1.455
89	50	Biased	20.54	19.117	-1.423
90	50	Biased	20.509	19.073	-1.436
92	50	Biased	20.725	19.282	-1.443
93	50	Unbiased	20.46	20.094	-0.366
94	50	Unbiased	20.681	20.313	-0.368
95	50	Unbiased	20.364	20.011	-0.353
96	100	Biased	20.515	18.577	-1.938
97	100	Biased	20.431	18.465	-1.966
98	100	Biased	20.421	18.426	-1.995
99	100	Unbiased	20.58	19.968	-0.612
100	100	Unbiased	20.409	19.807	-0.602
101	100	Unbiased	20.377	19.81	-0.567
102	0	Correlation	20.24	20.224	-0.016
103	0	Correlation	20.411	20.358	-0.053

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.24	20.325	20.411	0.12092	20.224	20.291	20.358	0.094752	-0.053	-0.0345	-0.016	0.026163
50	20.364	20.532	20.725	0.12987	18.989	19.554	20.313	0.56156	-1.455	-0.97771	-0.353	0.57573
100	20.377	20.456	20.58	0.076362	18.426	19.175	19.968	0.75554	-1.995	-1.28	-0.567	0.75221

Device Test: 18.27 RESET_RNMOS(Res_PD_RESETB4/RESETB4/1.6/3/0/0/2/@RESET_RNMOS)





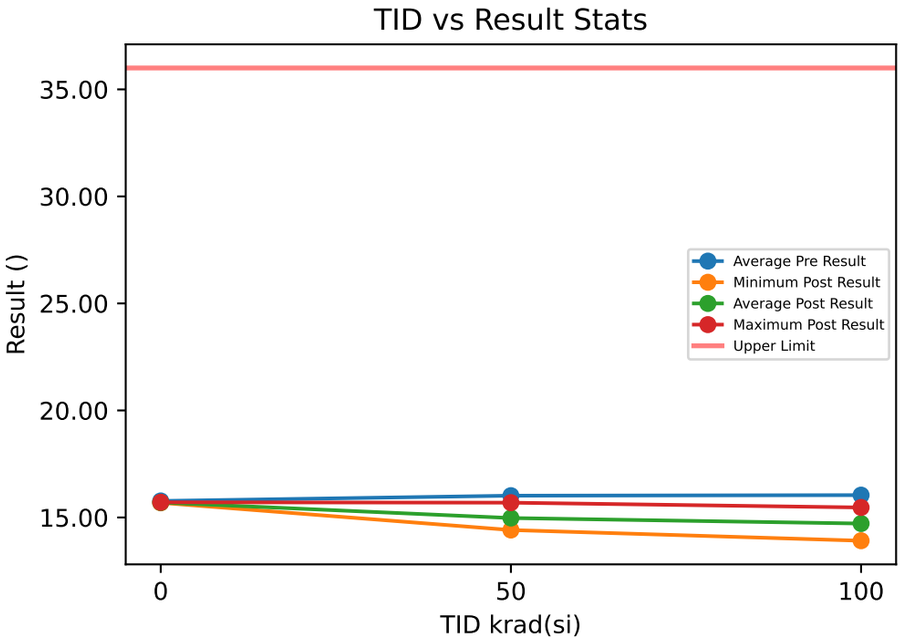
Test Results (Upper Limit = 36.0 ())

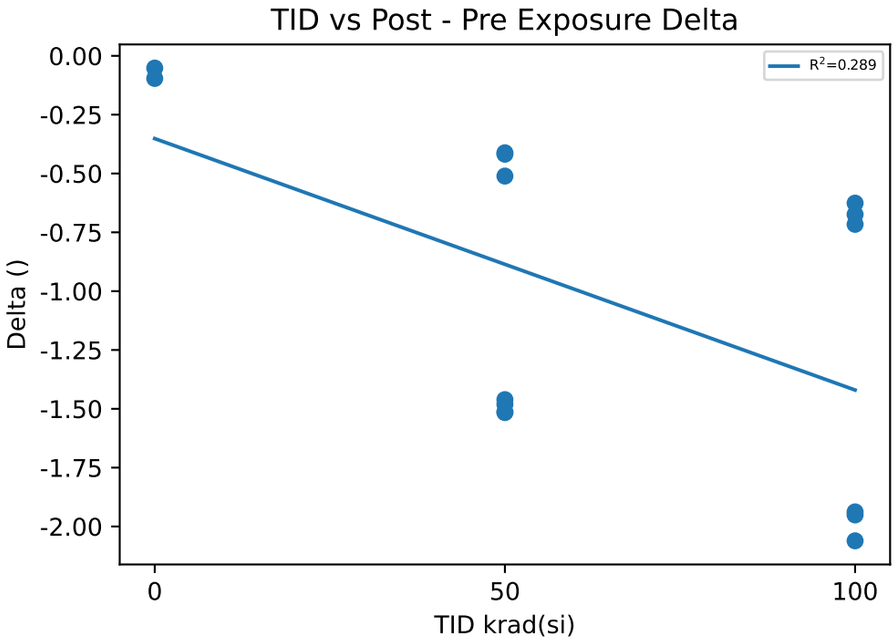
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.844	19.23	-0.614
89	50	Biased	19.914	19.308	-0.606
90	50	Biased	19.943	19.339	-0.604
92	50	Biased	20.257	19.634	-0.623
93	50	Unbiased	19.881	19.417	-0.464
94	50	Unbiased	20.093	19.62	-0.473
95	50	Unbiased	19.767	19.317	-0.45
96	100	Biased	19.973	19.232	-0.741
97	100	Biased	19.848	19.092	-0.756
98	100	Biased	19.77	18.999	-0.771
99	100	Unbiased	19.987	19.284	-0.703
100	100	Unbiased	19.807	19.121	-0.686
101	100	Unbiased	19.756	19.118	-0.638
102	0	Correlation	19.619	19.505	-0.114
103	0	Correlation	19.789	19.645	-0.144

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.619	19.704	19.789	0.12021	19.505	19.575	19.645	0.098995	-0.144	-0.129	-0.114	0.021213
50	19.767	19.957	20.257	0.16592	19.23	19.409	19.634	0.15854	-0.623	-0.54771	-0.45	0.08038
100	19.756	19.857	19.987	0.1007	18.999	19.141	19.284	0.1022	-0.771	-0.71583	-0.638	0.049805

Device Test: 18.28 PWRGD_RNMOS(Res_PD_PWRDG/PWRGD/1.6/3/0/0/2/@PWRGD_RNMOS)





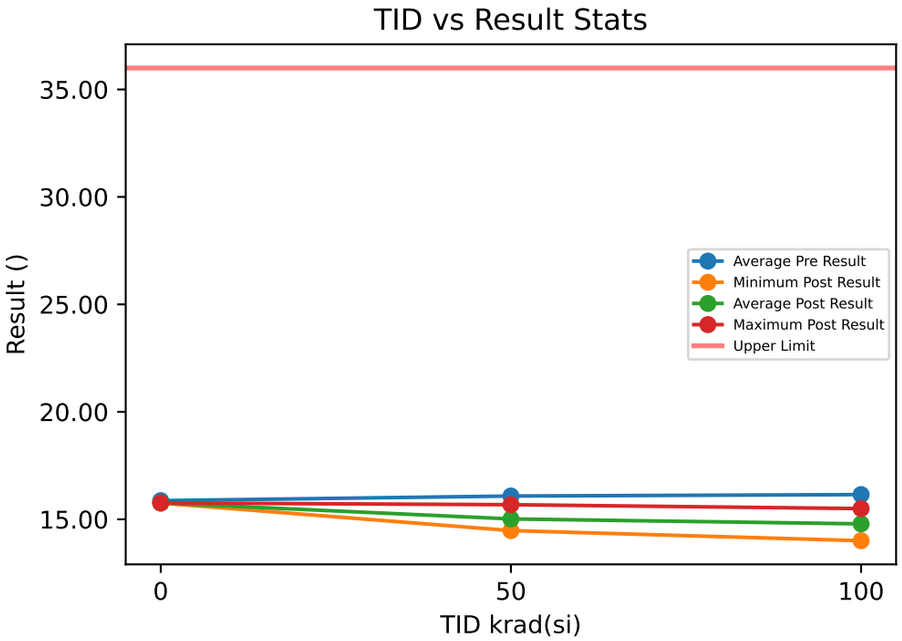
Test Results (Upper Limit = 36.0 ())

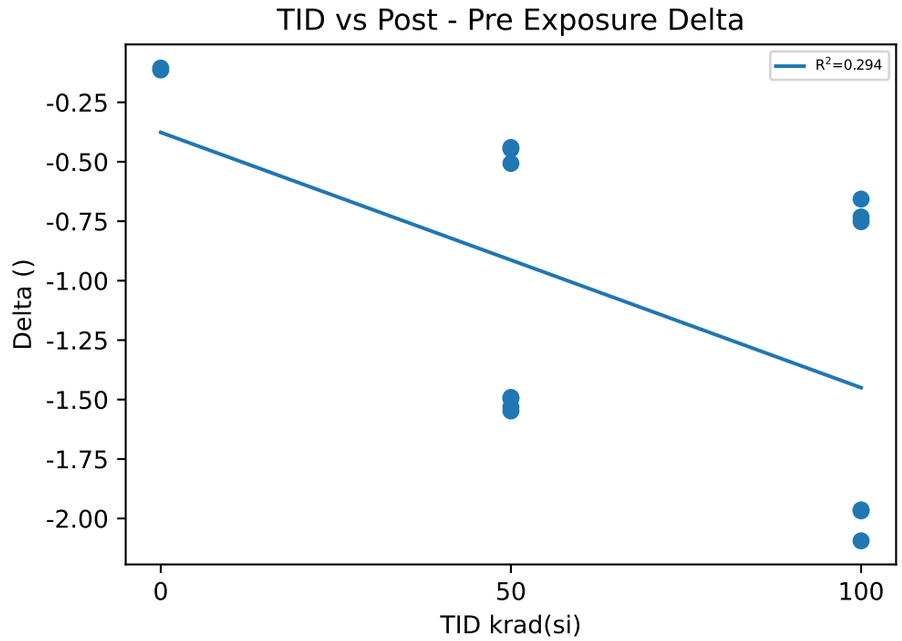
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	15.874	14.413	-1.461
89	50	Biased	16.012	14.496	-1.516
90	50	Biased	16.028	14.547	-1.481
92	50	Biased	16.11	14.597	-1.513
93	50	Unbiased	15.948	15.53	-0.418
94	50	Unbiased	16.202	15.691	-0.511
95	50	Unbiased	15.95	15.538	-0.412
96	100	Biased	16.247	14.186	-2.061
97	100	Biased	15.944	13.993	-1.951
98	100	Biased	15.851	13.913	-1.938
99	100	Unbiased	16.182	15.466	-0.716
100	100	Unbiased	16.046	15.372	-0.674
101	100	Unbiased	15.988	15.362	-0.626
102	0	Correlation	15.737	15.685	-0.052
103	0	Correlation	15.805	15.709	-0.096

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	15.737	15.771	15.805	0.048083	15.685	15.697	15.709	0.016971	-0.096	-0.074	-0.052	0.031113
50	15.874	16.018	16.202	0.11009	14.413	14.973	15.691	0.57864	-1.516	-1.0446	-0.412	0.56021
100	15.851	16.043	16.247	0.14875	13.913	14.715	15.466	0.75612	-2.061	-1.3277	-0.626	0.72008

Device Test: 18.29 WDO_RNMOS(Res_PD_WDOB/WDOB/1.6/3/0/0/2/@WDO_RNMOS)





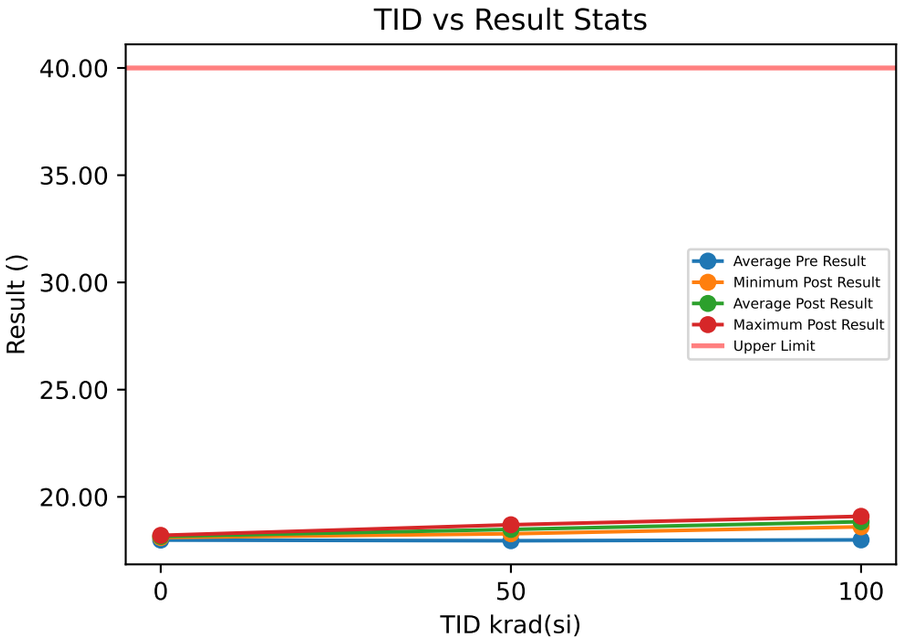
Test Results (Upper Limit = 36.0 ())

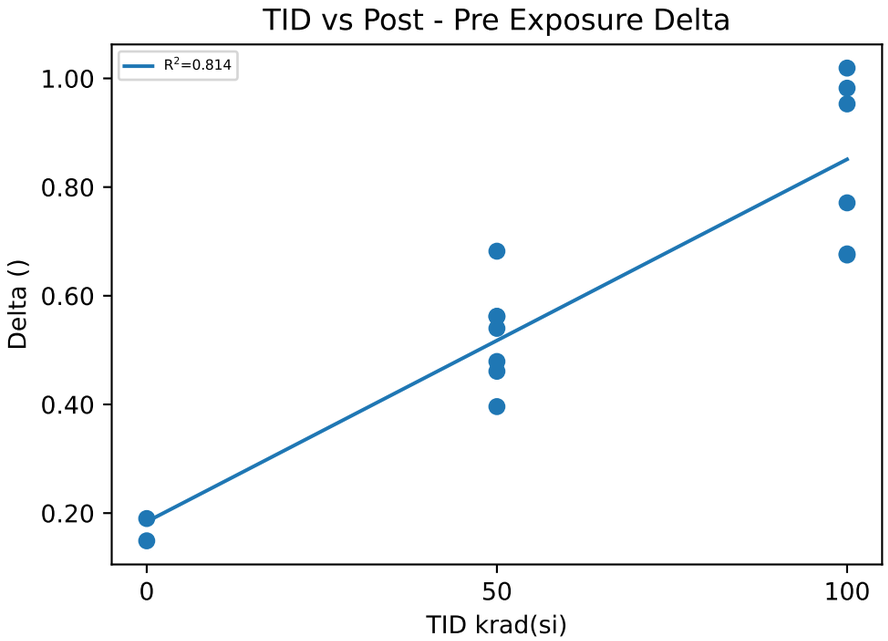
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	15.965	14.474	-1.491
89	50	Biased	16.035	14.504	-1.531
90	50	Biased	16.059	14.563	-1.496
92	50	Biased	16.262	14.714	-1.548
93	50	Unbiased	16.038	15.592	-0.446
94	50	Unbiased	16.186	15.679	-0.507
95	50	Unbiased	16.032	15.592	-0.44
96	100	Biased	16.341	14.247	-2.094
97	100	Biased	16.03	14.062	-1.968
98	100	Biased	15.967	14.003	-1.964
99	100	Unbiased	16.216	15.484	-0.732
100	100	Unbiased	16.25	15.498	-0.752
101	100	Unbiased	16.088	15.431	-0.657
102	0	Correlation	15.861	15.755	-0.106
103	0	Correlation	15.875	15.761	-0.114

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	15.861	15.868	15.875	0.0098995	15.755	15.758	15.761	0.0042426	-0.114	-0.11	-0.106	0.0056569
50	15.965	16.082	16.262	0.10334	14.474	15.017	15.679	0.57088	-1.548	-1.0656	-0.44	0.56315
100	15.967	16.149	16.341	0.14322	14.003	14.787	15.498	0.75339	-2.094	-1.3612	-0.657	0.71155

Device Test: 18.3 RESET_RPMOS_LOW_V(Res_PU_RESETB4/RESETB4/1.6/3/0/0/2/@RESET_RPMOS_LOW_V)





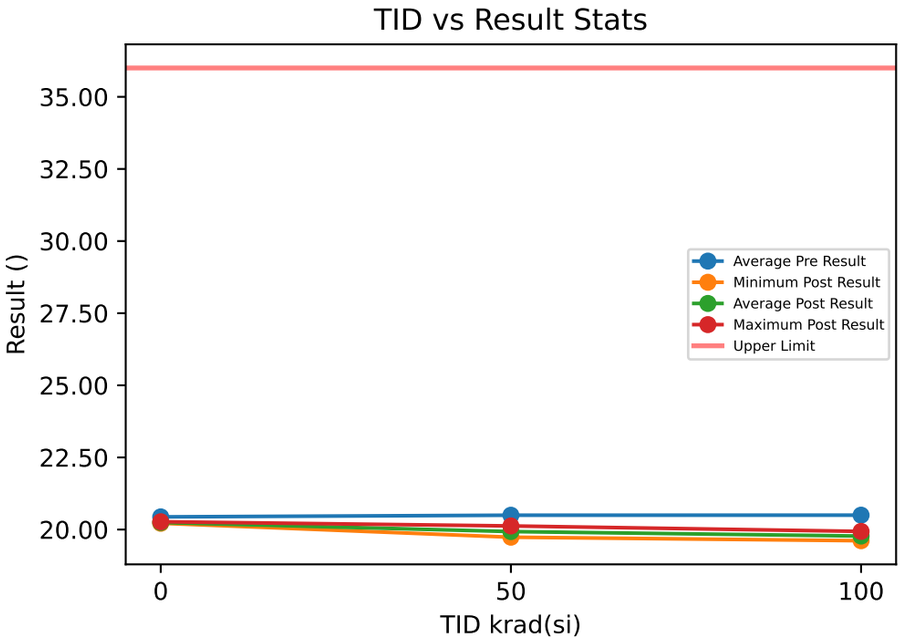
Test Results (Upper Limit = 40.0 ())

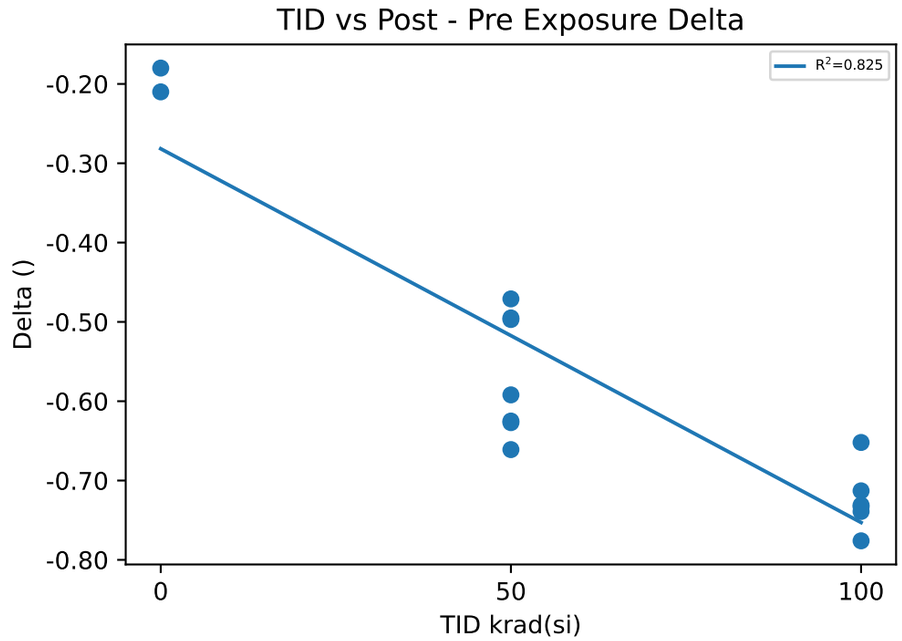
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	17.89	18.369	0.479
89	50	Biased	17.718	18.28	0.562
90	50	Biased	17.898	18.359	0.461
92	50	Biased	18.189	18.585	0.396
93	50	Unbiased	18.137	18.699	0.562
94	50	Unbiased	17.782	18.464	0.682
95	50	Unbiased	18.075	18.615	0.54
96	100	Biased	17.832	18.603	0.771
97	100	Biased	18.066	18.743	0.677
98	100	Biased	17.99	18.665	0.675
99	100	Unbiased	17.874	18.893	1.019
100	100	Unbiased	18.093	19.046	0.953
101	100	Unbiased	18.111	19.093	0.982
102	0	Correlation	17.915	18.105	0.19
103	0	Correlation	18.056	18.205	0.149

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.915	17.986	18.056	0.099702	18.105	18.155	18.205	0.070711	0.149	0.1695	0.19	0.028991
50	17.718	17.956	18.189	0.18067	18.28	18.482	18.699	0.15514	0.396	0.526	0.682	0.091704
100	17.832	17.994	18.111	0.11776	18.603	18.841	19.093	0.20271	0.675	0.84617	1.019	0.15704

Device Test: 18.30 RESET_RNMOS(Res_PD_RESETB1/RESETB1/1.6/14/0/0/2/@RESET_RNMOS)





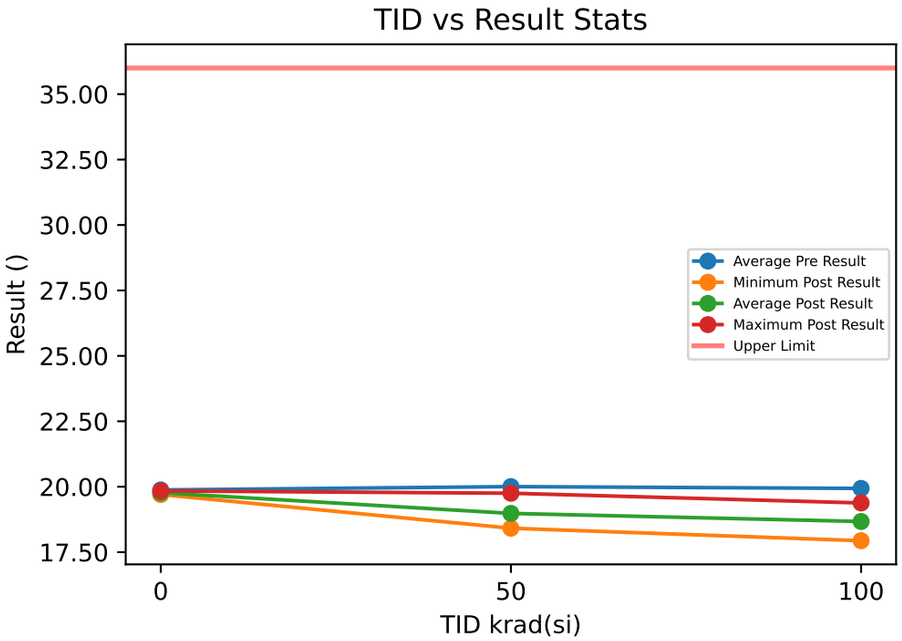
Test Results (Upper Limit = 36.0 ())

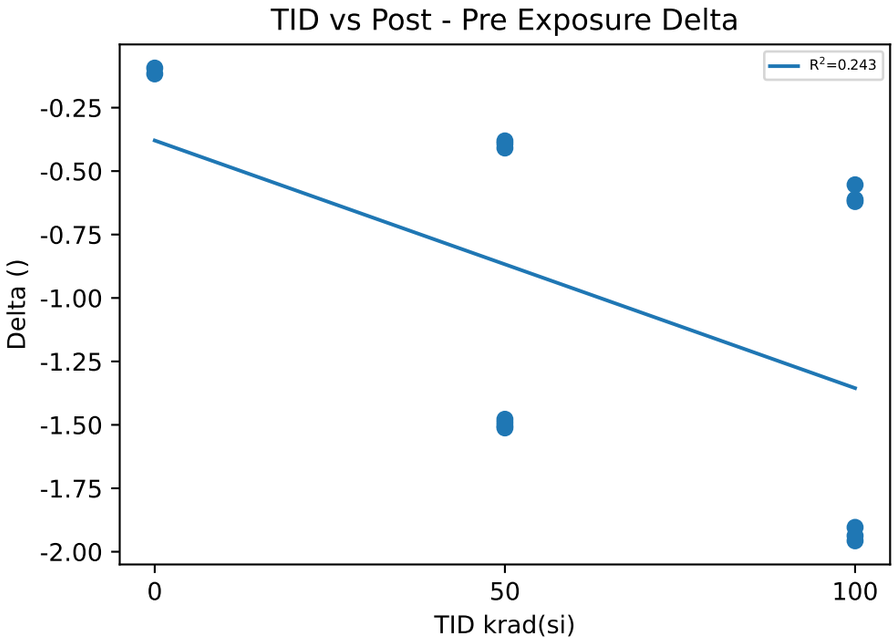
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	20.396	19.735	-0.661
89	50	Biased	20.502	19.877	-0.625
90	50	Biased	20.582	19.955	-0.627
92	50	Biased	20.388	19.796	-0.592
93	50	Unbiased	20.501	20.03	-0.471
94	50	Unbiased	20.622	20.125	-0.497
95	50	Unbiased	20.487	19.992	-0.495
96	100	Biased	20.577	19.846	-0.731
97	100	Biased	20.385	19.646	-0.739
98	100	Biased	20.389	19.613	-0.776
99	100	Unbiased	20.669	19.936	-0.733
100	100	Unbiased	20.482	19.769	-0.713
101	100	Unbiased	20.491	19.839	-0.652
102	0	Correlation	20.398	20.218	-0.18
103	0	Correlation	20.481	20.271	-0.21

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.398	20.44	20.481	0.05869	20.218	20.245	20.271	0.037477	-0.21	-0.195	-0.18	0.021213
50	20.388	20.497	20.622	0.086673	19.735	19.93	20.125	0.13619	-0.661	-0.56686	-0.471	0.077163
100	20.385	20.499	20.669	0.10994	19.613	19.775	19.936	0.12488	-0.776	-0.724	-0.652	0.0409

Device Test: 18.31 RESET_RNMOS(Res_PD_RESETB2/RESETB2/1.6/14/0/0/2/@RESET_RNMOS)





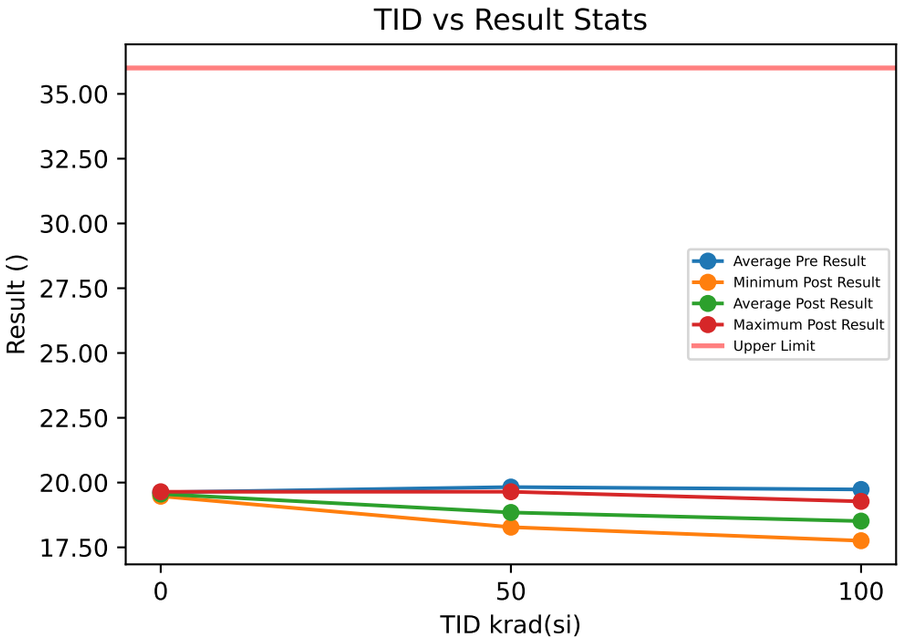
Test Results (Upper Limit = 36.0 ())

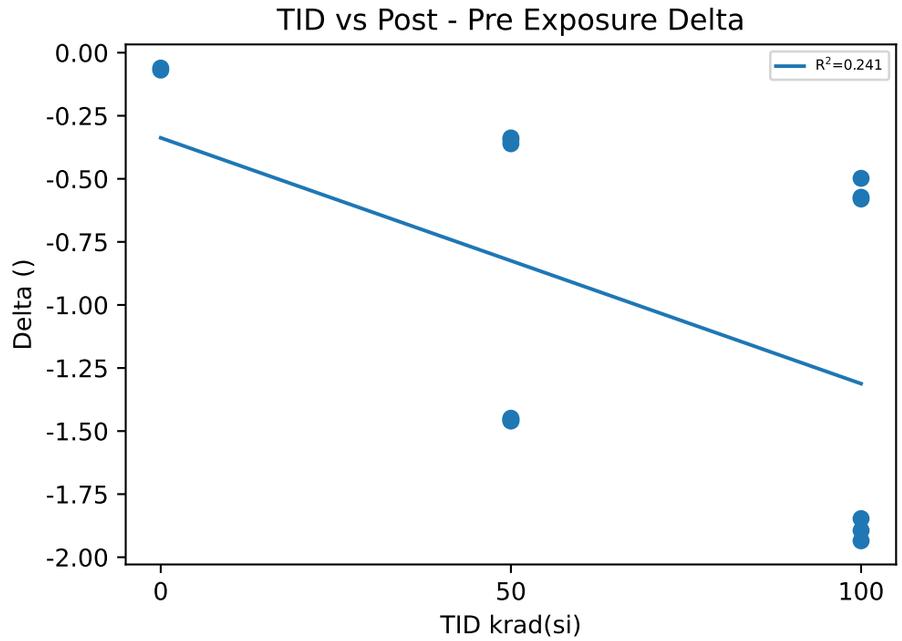
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.927	18.415	-1.512
89	50	Biased	20	18.496	-1.504
90	50	Biased	19.98	18.489	-1.491
92	50	Biased	20.182	18.704	-1.478
93	50	Unbiased	19.902	19.521	-0.381
94	50	Unbiased	20.161	19.752	-0.409
95	50	Unbiased	19.88	19.488	-0.392
96	100	Biased	19.948	18.044	-1.904
97	100	Biased	19.949	17.992	-1.957
98	100	Biased	19.874	17.937	-1.937
99	100	Unbiased	20	19.38	-0.62
100	100	Unbiased	19.981	19.369	-0.612
101	100	Unbiased	19.862	19.308	-0.554
102	0	Correlation	19.796	19.702	-0.094
103	0	Correlation	19.957	19.84	-0.117

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.796	19.877	19.957	0.11384	19.702	19.771	19.84	0.097581	-0.117	-0.1055	-0.094	0.016263
50	19.88	20.005	20.182	0.12154	18.415	18.981	19.752	0.57987	-1.512	-1.0239	-0.381	0.58933
100	19.862	19.936	20	0.056131	17.937	18.672	19.38	0.7468	-1.957	-1.264	-0.554	0.73304

Device Test: 18.32 RESET_RNMOS(Res_PD_RESETB3/RESETB3/1.6/14/0/0/2/@RESET_RNMOS)





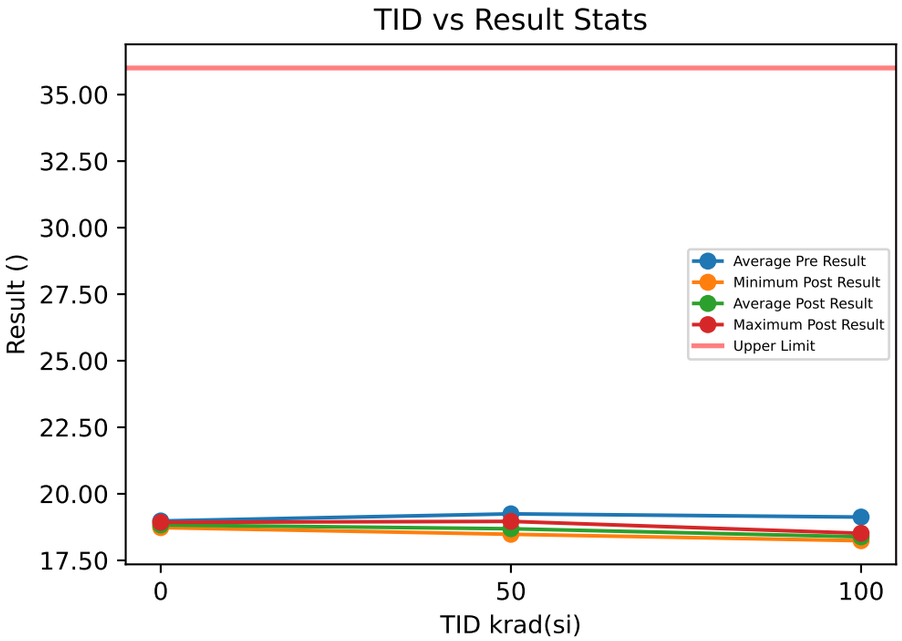
Test Results (Upper Limit = 36.0 ())

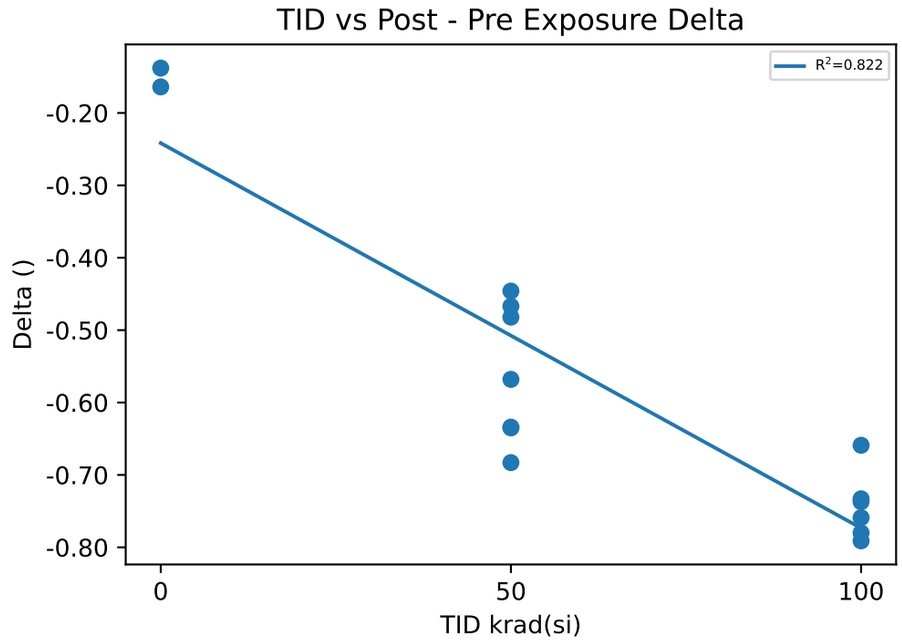
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.74	18.28	-1.46
89	50	Biased	19.848	18.396	-1.452
90	50	Biased	19.82	18.371	-1.449
92	50	Biased	20.001	18.542	-1.459
93	50	Unbiased	19.711	19.366	-0.345
94	50	Unbiased	20.007	19.646	-0.361
95	50	Unbiased	19.657	19.319	-0.338
96	100	Biased	19.797	17.95	-1.847
97	100	Biased	19.694	17.8	-1.894
98	100	Biased	19.691	17.756	-1.935
99	100	Unbiased	19.854	19.274	-0.58
100	100	Unbiased	19.712	19.139	-0.573
101	100	Unbiased	19.658	19.16	-0.498
102	0	Correlation	19.534	19.473	-0.061
103	0	Correlation	19.714	19.645	-0.069

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.534	19.624	19.714	0.12728	19.473	19.559	19.645	0.12162	-0.069	-0.065	-0.061	0.0056569
50	19.657	19.826	20.007	0.13729	18.28	18.846	19.646	0.57373	-1.46	-0.98057	-0.338	0.59177
100	19.658	19.734	19.854	0.074936	17.756	18.513	19.274	0.74673	-1.935	-1.2212	-0.498	0.73595

Device Test: 18.33 RESET_RNMOS(Res_PD_RESETB4/RESETB4/1.6/14/0/0/2/@RESET_RNMOS)





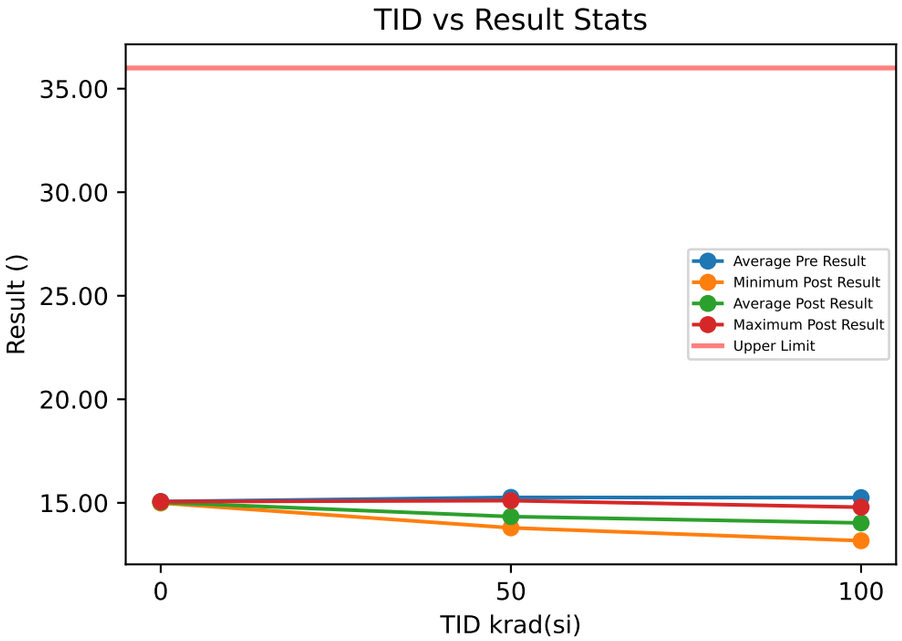
Test Results (Upper Limit = 36.0 ())

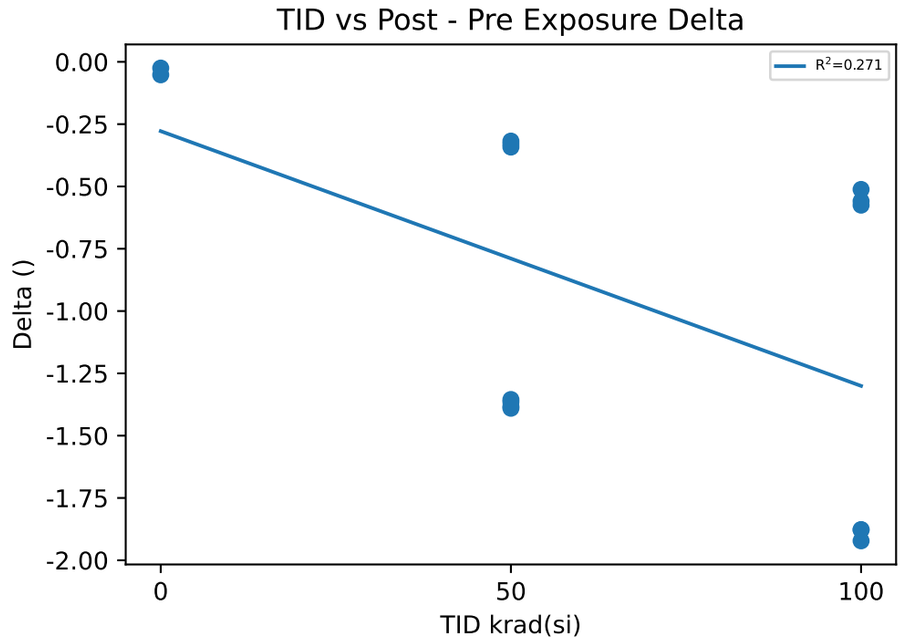
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.163	18.48	-0.683
89	50	Biased	19.214	18.58	-0.634
90	50	Biased	19.267	18.632	-0.635
92	50	Biased	19.508	18.94	-0.568
93	50	Unbiased	19.116	18.649	-0.467
94	50	Unbiased	19.41	18.964	-0.446
95	50	Unbiased	19.052	18.57	-0.482
96	100	Biased	19.259	18.5	-0.759
97	100	Biased	19.101	18.321	-0.78
98	100	Biased	19.029	18.238	-0.791
99	100	Unbiased	19.25	18.517	-0.733
100	100	Unbiased	19.091	18.354	-0.737
101	100	Unbiased	19.031	18.372	-0.659
102	0	Correlation	18.868	18.73	-0.138
103	0	Correlation	19.093	18.929	-0.164

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.868	18.98	19.093	0.1591	18.73	18.829	18.929	0.14071	-0.164	-0.151	-0.138	0.018385
50	19.052	19.247	19.508	0.16249	18.48	18.688	18.964	0.1885	-0.683	-0.55929	-0.446	0.094885
100	19.029	19.127	19.259	0.10329	18.238	18.384	18.517	0.10721	-0.791	-0.74317	-0.659	0.047161

Device Test: 18.34 PWRGD_RNMOS(Res_PD_PWRDG/PWRGD/1.6/14/0/0/2/@PWRGD_RNMOS)





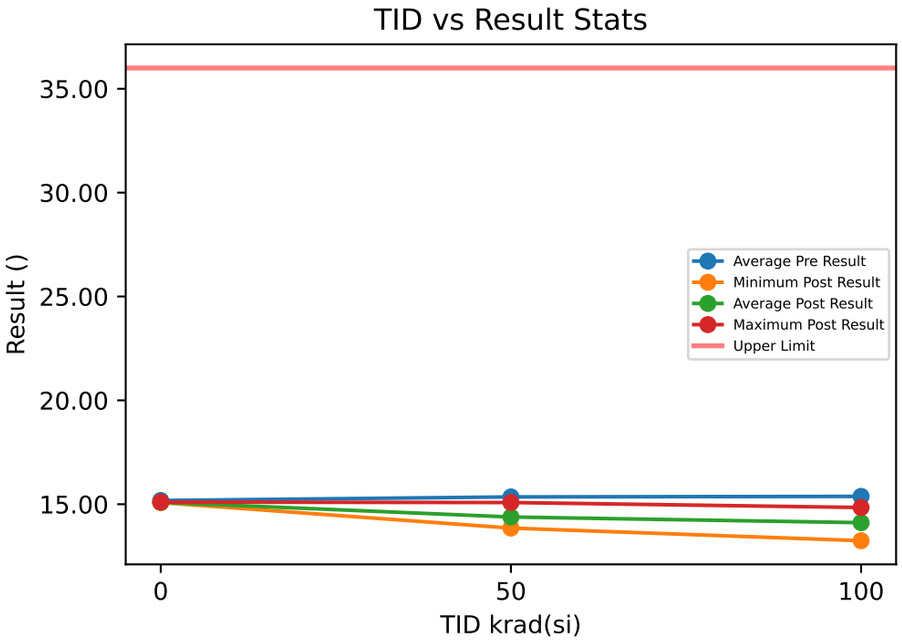
Test Results (Upper Limit = 36.0 ())

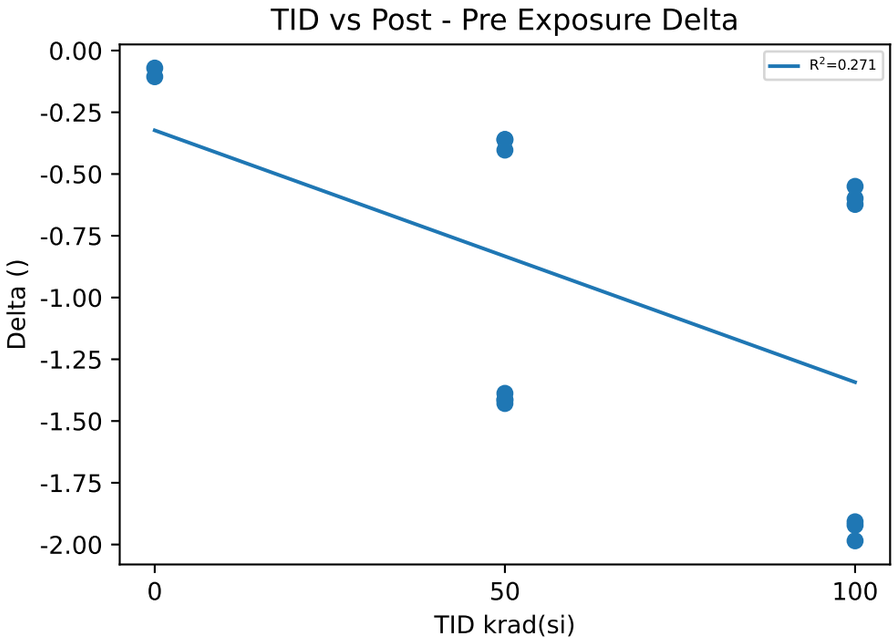
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	15.157	13.792	-1.365
89	50	Biased	15.252	13.862	-1.39
90	50	Biased	15.277	13.922	-1.355
92	50	Biased	15.329	13.946	-1.383
93	50	Unbiased	15.166	14.848	-0.318
94	50	Unbiased	15.448	15.106	-0.342
95	50	Unbiased	15.201	14.871	-0.33
96	100	Biased	15.417	13.539	-1.878
97	100	Biased	15.165	13.288	-1.877
98	100	Biased	15.092	13.17	-1.922
99	100	Unbiased	15.348	14.789	-0.559
100	100	Unbiased	15.272	14.697	-0.575
101	100	Unbiased	15.207	14.695	-0.512
102	0	Correlation	15.015	14.99	-0.025
103	0	Correlation	15.11	15.058	-0.052

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	15.015	15.062	15.11	0.067175	14.99	15.024	15.058	0.048083	-0.052	-0.0385	-0.025	0.019092
50	15.157	15.261	15.448	0.10277	13.792	14.335	15.106	0.57524	-1.39	-0.92614	-0.318	0.5578
100	15.092	15.25	15.417	0.12001	13.17	14.03	14.789	0.77388	-1.922	-1.2205	-0.512	0.73643

Device Test: 18.35 WDO_RNMOS(Res_PD_WDOB/WDOB/1.6/14/0/0/2/@WDO_RNMOS)





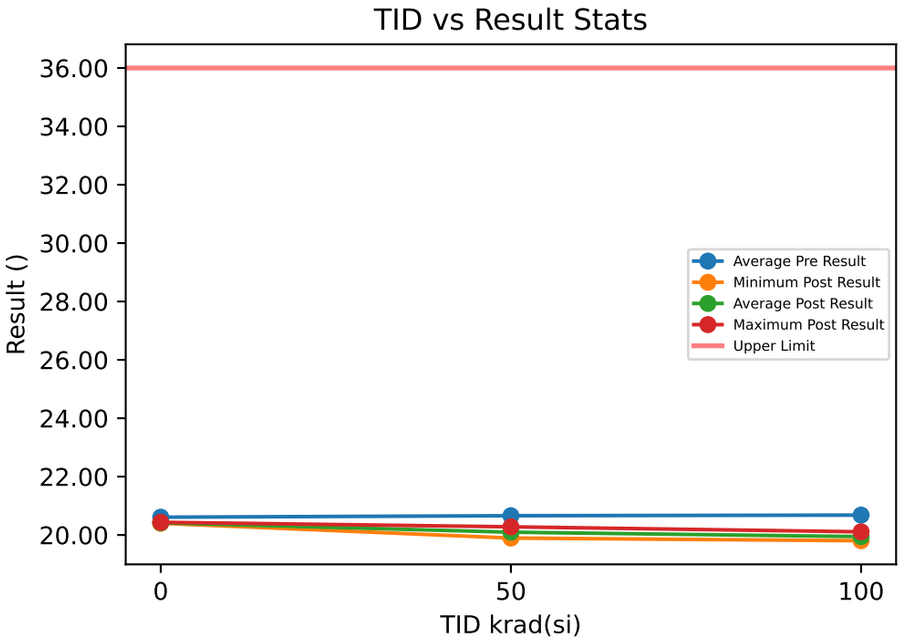
Test Results (Upper Limit = 36.0 ())

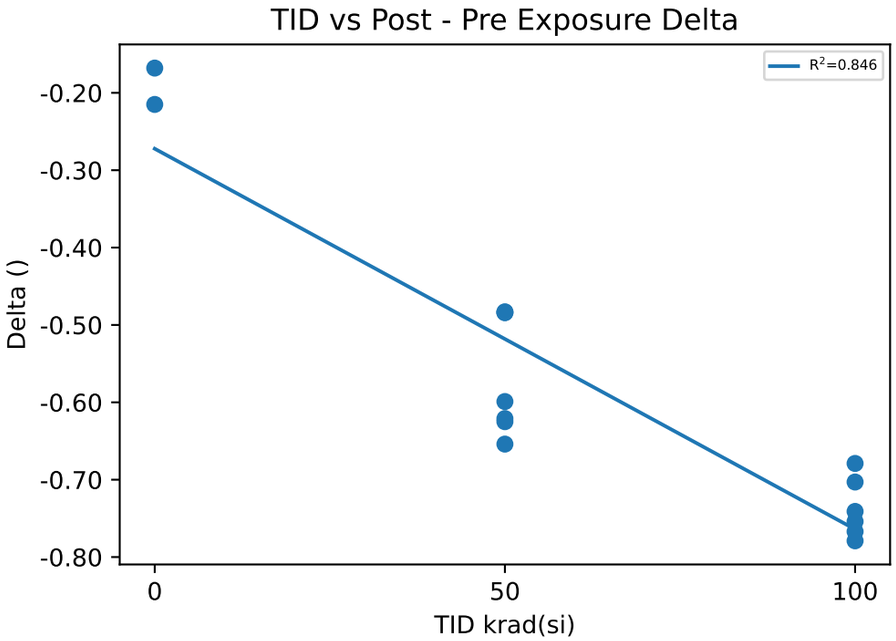
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	15.266	13.852	-1.414
89	50	Biased	15.314	13.885	-1.429
90	50	Biased	15.335	13.947	-1.388
92	50	Biased	15.475	14.061	-1.414
93	50	Unbiased	15.284	14.923	-0.361
94	50	Unbiased	15.485	15.082	-0.403
95	50	Unbiased	15.299	14.939	-0.36
96	100	Biased	15.531	13.609	-1.922
97	100	Biased	15.285	13.377	-1.908
98	100	Biased	15.228	13.243	-1.985
99	100	Unbiased	15.423	14.824	-0.599
100	100	Unbiased	15.465	14.842	-0.623
101	100	Unbiased	15.327	14.777	-0.55
102	0	Correlation	15.15	15.079	-0.071
103	0	Correlation	15.208	15.102	-0.106

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	15.15	15.179	15.208	0.041012	15.079	15.091	15.102	0.016263	-0.106	-0.0885	-0.071	0.024749
50	15.266	15.351	15.485	0.090715	13.852	14.384	15.082	0.56466	-1.429	-0.967	-0.36	0.55439
100	15.228	15.377	15.531	0.11553	13.243	14.112	14.842	0.77852	-1.985	-1.2645	-0.55	0.73898

Device Test: 18.36 RESET_RNMOS(Res_PD_RESETB1/RESETB1/7/3/0/0/2/@RESET_RNMOS)





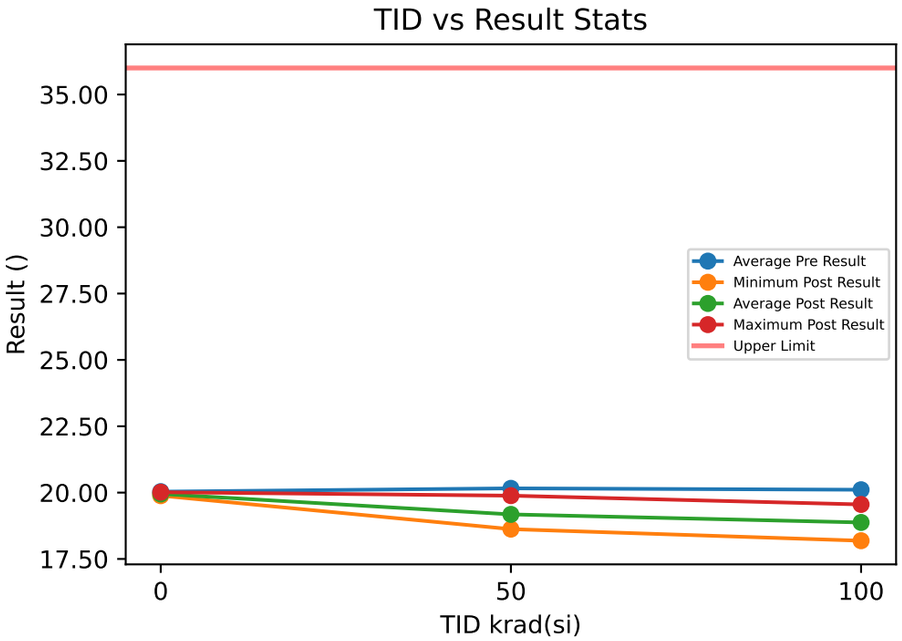
Test Results (Upper Limit = 36.0 ())

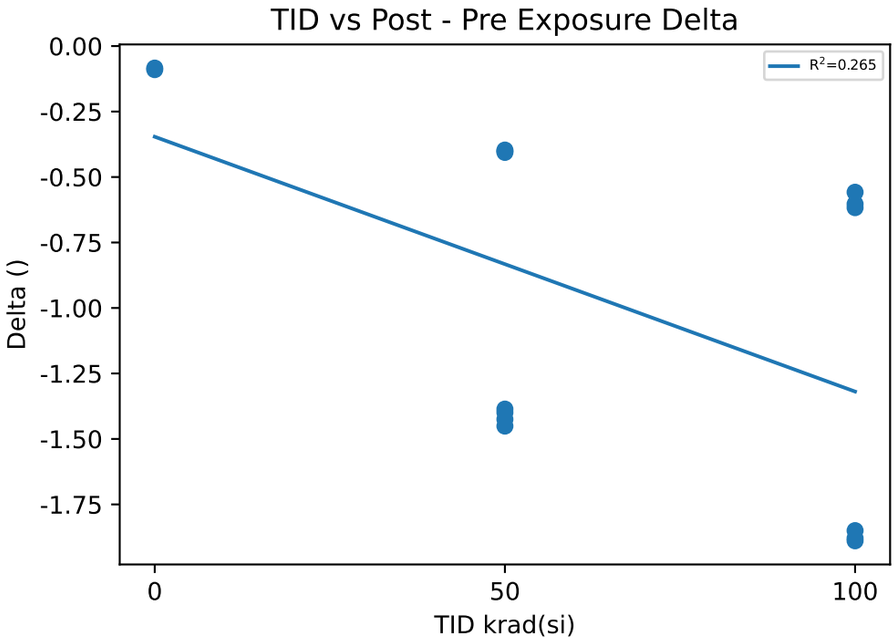
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	20.549	19.895	-0.654
89	50	Biased	20.677	20.052	-0.625
90	50	Biased	20.717	20.096	-0.621
92	50	Biased	20.583	19.984	-0.599
93	50	Unbiased	20.697	20.213	-0.484
94	50	Unbiased	20.764	20.28	-0.484
95	50	Unbiased	20.633	20.15	-0.483
96	100	Biased	20.78	20.026	-0.754
97	100	Biased	20.571	19.804	-0.767
98	100	Biased	20.594	19.815	-0.779
99	100	Unbiased	20.85	20.109	-0.741
100	100	Unbiased	20.634	19.931	-0.703
101	100	Unbiased	20.661	19.982	-0.679
102	0	Correlation	20.569	20.401	-0.168
103	0	Correlation	20.651	20.436	-0.215

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.569	20.61	20.651	0.057983	20.401	20.419	20.436	0.024749	-0.215	-0.1915	-0.168	0.033234
50	20.549	20.66	20.764	0.07605	19.895	20.096	20.28	0.1325	-0.654	-0.56429	-0.483	0.077088
100	20.571	20.682	20.85	0.11012	19.804	19.945	20.109	0.11983	-0.779	-0.73717	-0.679	0.038701

Device Test: 18.37 RESET_RNMOS(Res_PD_RESETB2/RESETB2/7/3/0/0/2/@RESET_RNMOS)





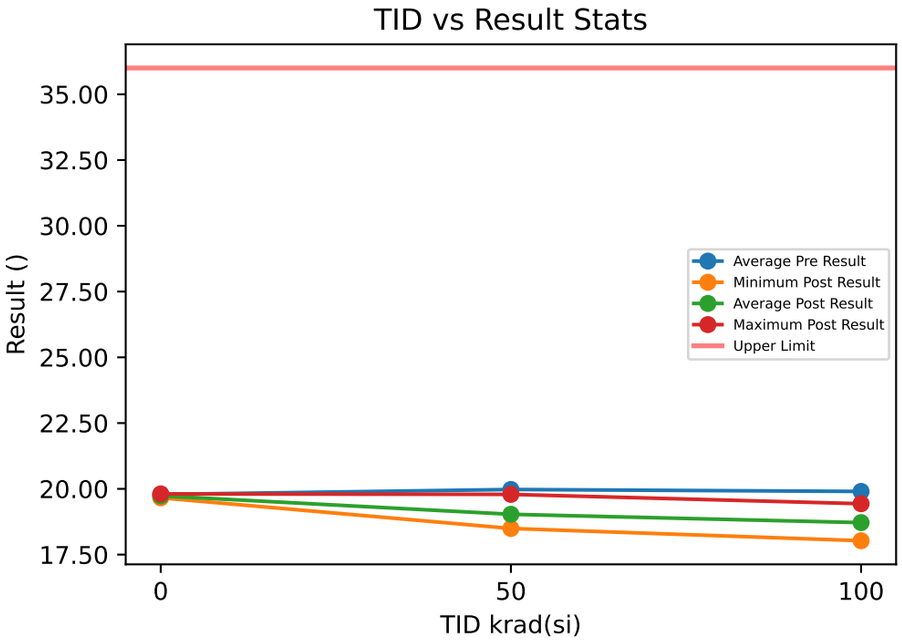
Test Results (Upper Limit = 36.0 ())

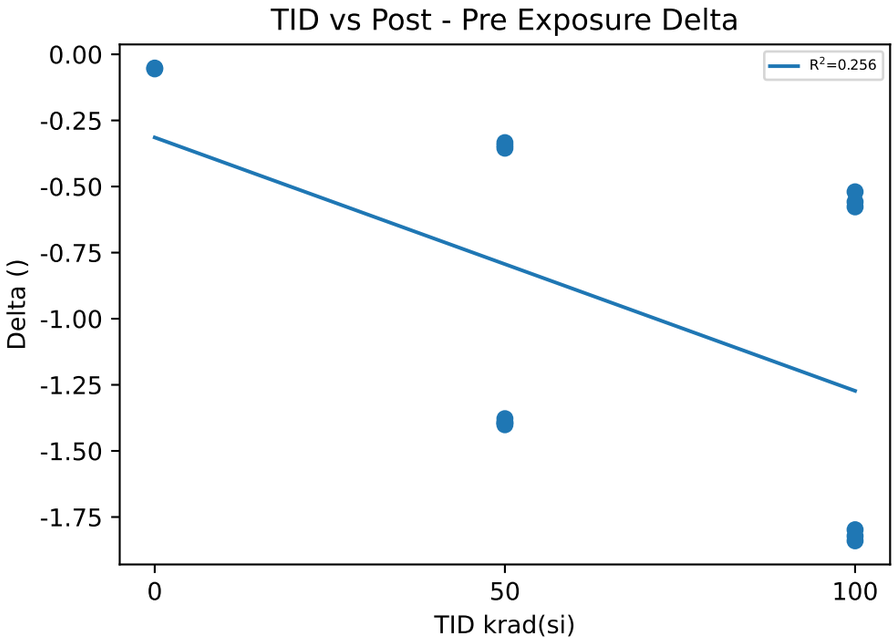
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	20.075	18.624	-1.451
89	50	Biased	20.143	18.744	-1.399
90	50	Biased	20.115	18.69	-1.425
92	50	Biased	20.351	18.965	-1.386
93	50	Unbiased	20.101	19.704	-0.397
94	50	Unbiased	20.291	19.885	-0.406
95	50	Unbiased	20.043	19.642	-0.401
96	100	Biased	20.127	18.277	-1.85
97	100	Biased	20.131	18.242	-1.889
98	100	Biased	20.066	18.187	-1.879
99	100	Unbiased	20.171	19.554	-0.617
100	100	Unbiased	20.129	19.526	-0.603
101	100	Unbiased	20.023	19.465	-0.558
102	0	Correlation	19.968	19.884	-0.084
103	0	Correlation	20.105	20.015	-0.09

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.968	20.037	20.105	0.096874	19.884	19.95	20.015	0.092631	-0.09	-0.087	-0.084	0.0042426
50	20.043	20.16	20.351	0.11572	18.624	19.179	19.885	0.54323	-1.451	-0.98071	-0.397	0.54235
100	20.023	20.108	20.171	0.053458	18.187	18.875	19.554	0.70208	-1.889	-1.2327	-0.558	0.70147

Device Test: 18.38 RESET_RNMOS(Res_PD_RESETB3/RESETB3/7/3/0/0/2/@RESET_RNMOS)





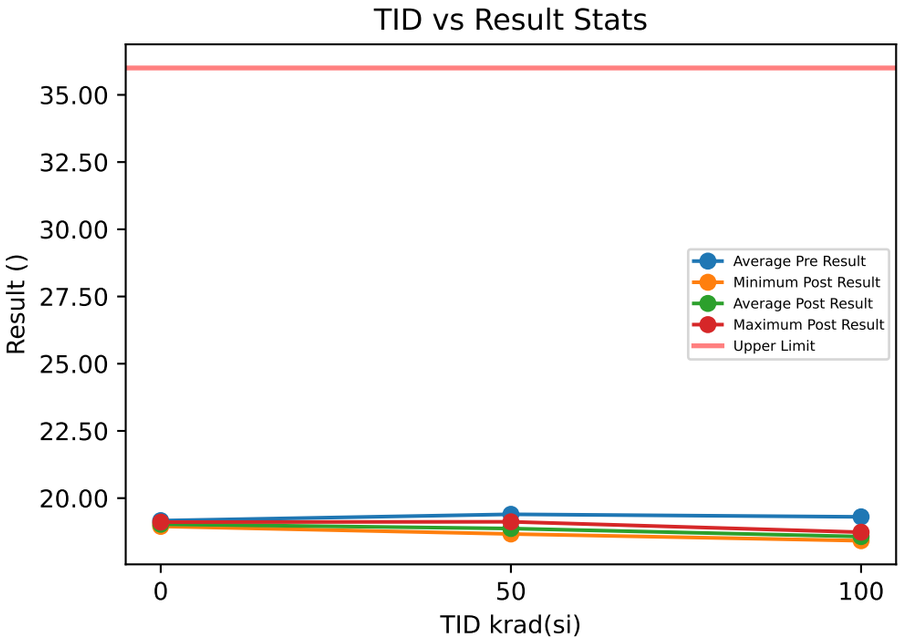
Test Results (Upper Limit = 36.0 ())

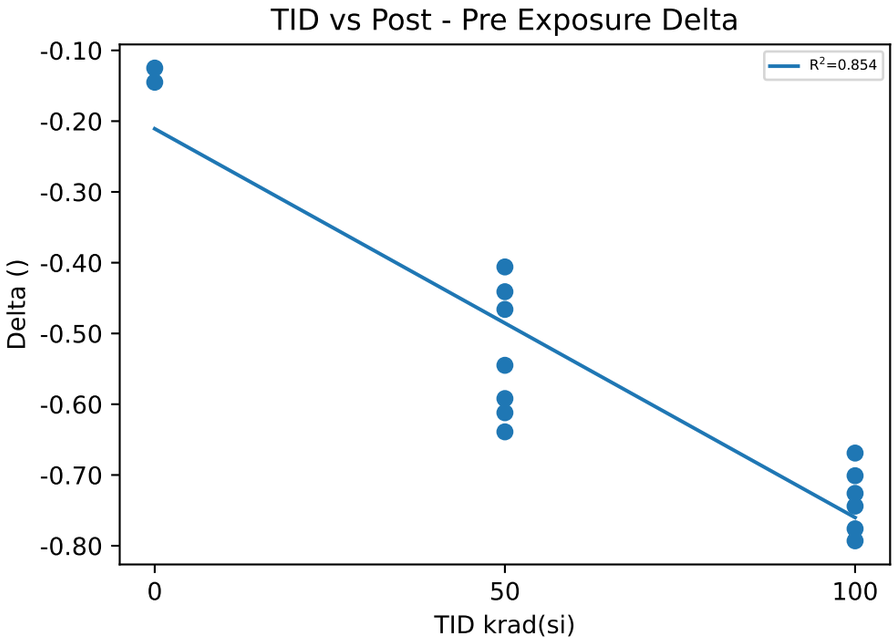
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.895	18.494	-1.401
89	50	Biased	19.988	18.595	-1.393
90	50	Biased	19.945	18.552	-1.393
92	50	Biased	20.152	18.774	-1.378
93	50	Unbiased	19.902	19.557	-0.345
94	50	Unbiased	20.124	19.79	-0.334
95	50	Unbiased	19.822	19.467	-0.355
96	100	Biased	19.969	18.171	-1.798
97	100	Biased	19.877	18.055	-1.822
98	100	Biased	19.868	18.028	-1.84
99	100	Unbiased	20.012	19.435	-0.577
100	100	Unbiased	19.852	19.294	-0.558
101	100	Unbiased	19.833	19.313	-0.52
102	0	Correlation	19.714	19.659	-0.055
103	0	Correlation	19.86	19.808	-0.052

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.714	19.787	19.86	0.10324	19.659	19.733	19.808	0.10536	-0.055	-0.0535	-0.052	0.0021213
50	19.822	19.975	20.152	0.12229	18.494	19.033	19.79	0.55027	-1.401	-0.94271	-0.334	0.5595
100	19.833	19.902	20.012	0.071597	18.028	18.716	19.435	0.69495	-1.84	-1.1858	-0.52	0.69507

Device Test: 18.39 RESET_RNMOS(Res_PD_RESETB4/RESETB4/7/3/0/0/2/@RESET_RNMOS)





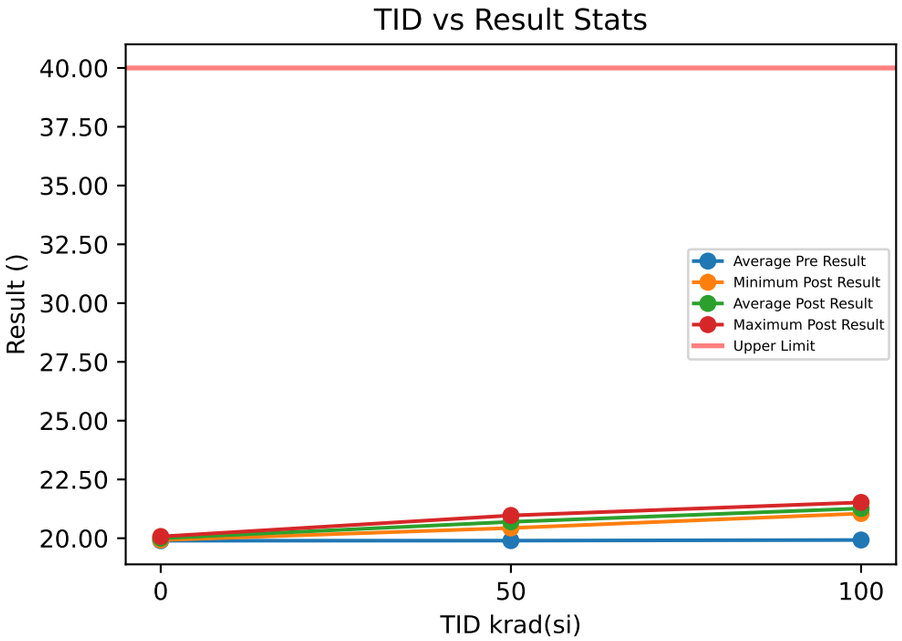
Test Results (Upper Limit = 36.0 ())

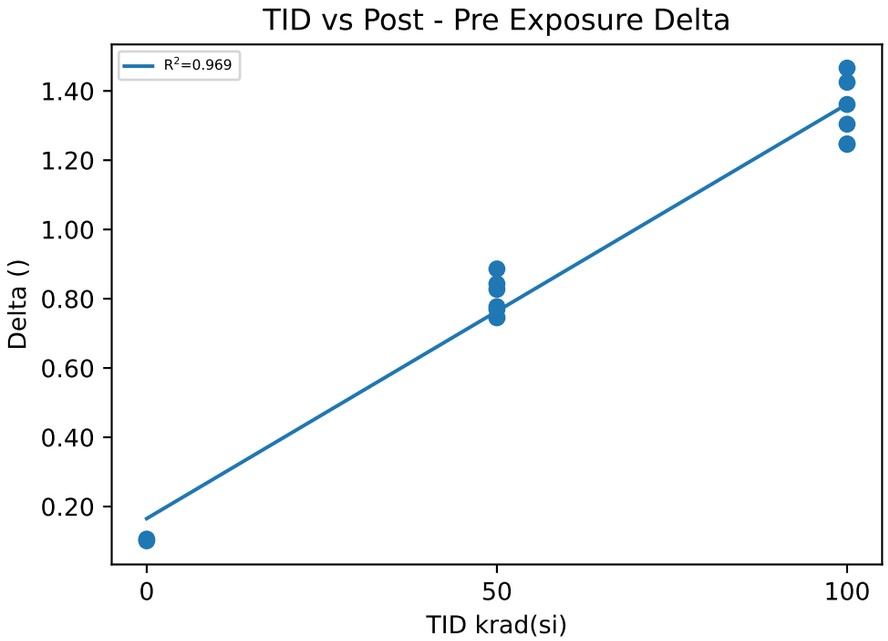
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.306	18.667	-0.639
89	50	Biased	19.367	18.755	-0.612
90	50	Biased	19.395	18.803	-0.592
92	50	Biased	19.665	19.12	-0.545
93	50	Unbiased	19.32	18.879	-0.441
94	50	Unbiased	19.52	19.114	-0.406
95	50	Unbiased	19.214	18.748	-0.466
96	100	Biased	19.439	18.695	-0.744
97	100	Biased	19.28	18.504	-0.776
98	100	Biased	19.209	18.416	-0.793
99	100	Unbiased	19.433	18.732	-0.701
100	100	Unbiased	19.253	18.527	-0.726
101	100	Unbiased	19.211	18.542	-0.669
102	0	Correlation	19.074	18.949	-0.125
103	0	Correlation	19.253	19.108	-0.145

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.074	19.163	19.253	0.12657	18.949	19.029	19.108	0.11243	-0.145	-0.135	-0.125	0.014142
50	19.214	19.398	19.665	0.1503	18.667	18.869	19.12	0.1807	-0.639	-0.52871	-0.406	0.091338
100	19.209	19.304	19.439	0.10556	18.416	18.569	18.732	0.12048	-0.793	-0.73483	-0.669	0.046301

Device Test: 18.4 PWRGD_RPMOS_LOW_V(Res_PU_PWRDG/PWRGD/1.6/3/0/0/2/@PWRGD_RPMOS_LOW_V)





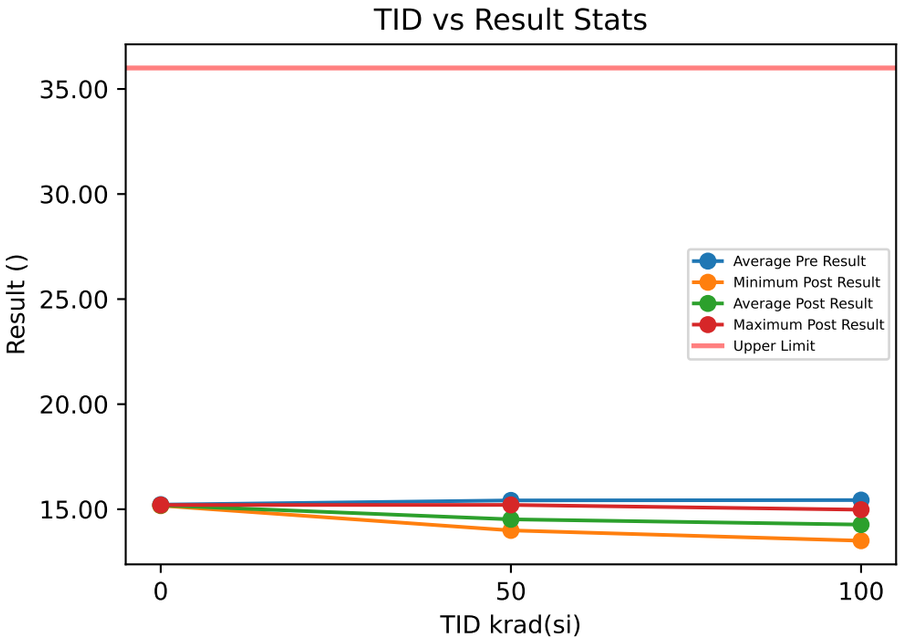
Test Results (Upper Limit = 40.0 ())

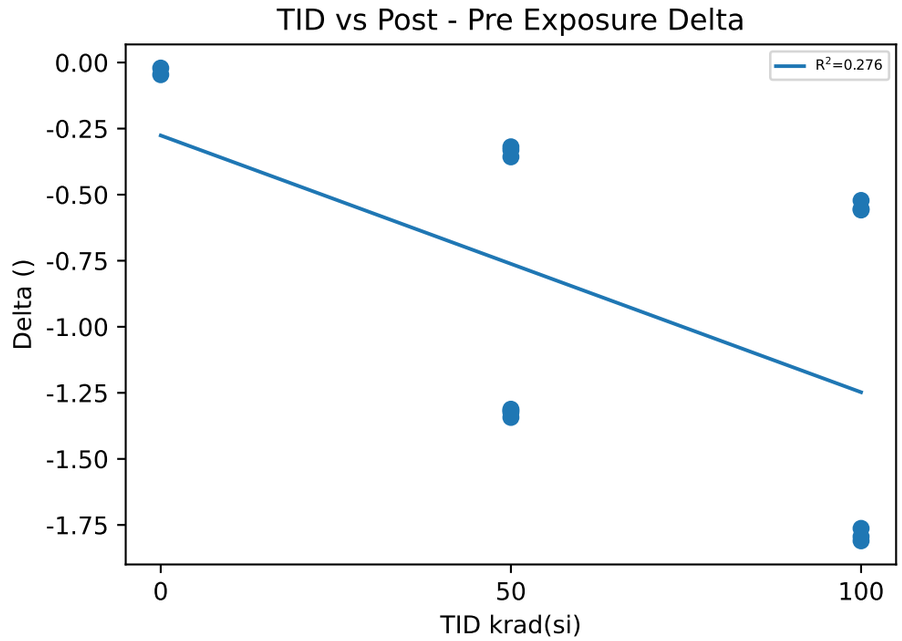
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.822	20.591	0.769
89	50	Biased	19.709	20.536	0.827
90	50	Biased	19.838	20.681	0.843
92	50	Biased	20.082	20.968	0.886
93	50	Unbiased	20.079	20.856	0.777
94	50	Unbiased	19.689	20.434	0.745
95	50	Unbiased	20.067	20.813	0.746
96	100	Biased	19.768	21.129	1.361
97	100	Biased	20.057	21.523	1.466
98	100	Biased	19.935	21.36	1.425
99	100	Unbiased	19.804	21.051	1.247
100	100	Unbiased	19.903	21.149	1.246
101	100	Unbiased	20.078	21.382	1.304
102	0	Correlation	19.821	19.922	0.101
103	0	Correlation	19.967	20.073	0.106

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.821	19.894	19.967	0.10324	19.922	19.998	20.073	0.10677	0.101	0.1035	0.106	0.0035355
50	19.689	19.898	20.082	0.1751	20.434	20.697	20.968	0.19095	0.745	0.799	0.886	0.053849
100	19.768	19.924	20.078	0.12705	21.051	21.266	21.523	0.18277	1.246	1.3415	1.466	0.091989

Device Test: 18.40 PWRGD_RNMOS(Res_PD_PWRDG/PWRGD/7/3/0/0/2/@PWRGD_RNMOS)





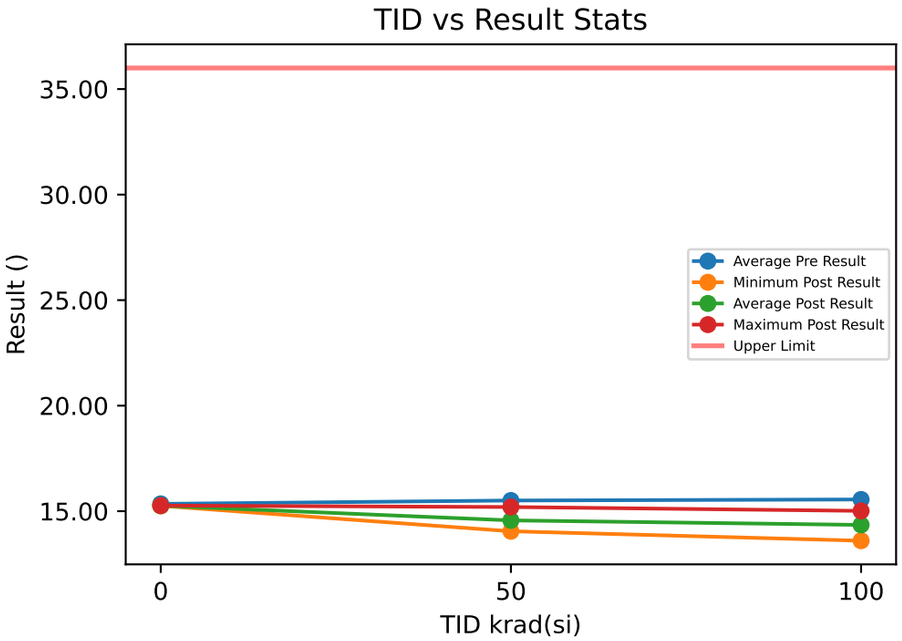
Test Results (Upper Limit = 36.0 ())

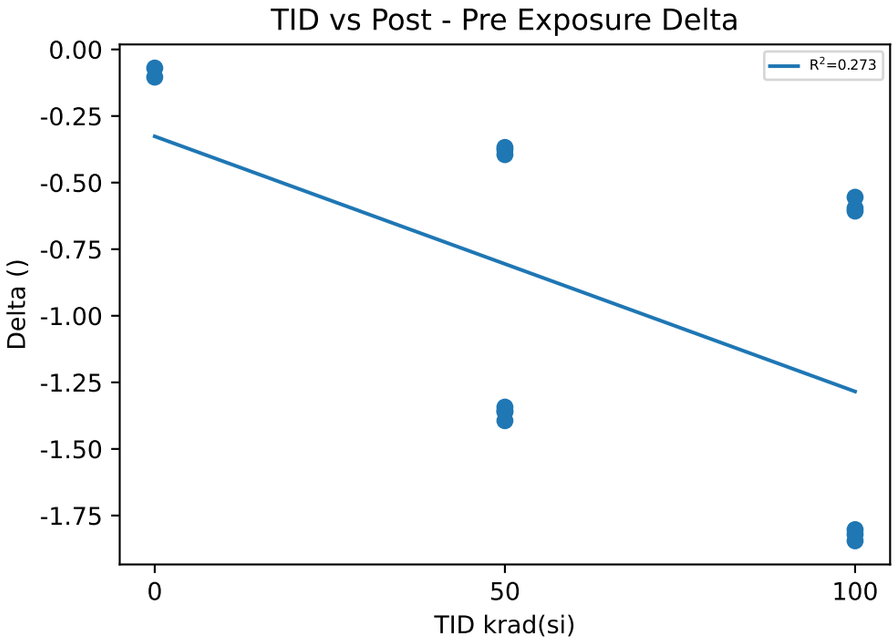
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	15.316	13.992	-1.324
89	50	Biased	15.414	14.071	-1.343
90	50	Biased	15.429	14.117	-1.312
92	50	Biased	15.485	14.168	-1.317
93	50	Unbiased	15.36	15.029	-0.331
94	50	Unbiased	15.562	15.205	-0.357
95	50	Unbiased	15.368	15.049	-0.319
96	100	Biased	15.597	13.787	-1.81
97	100	Biased	15.343	13.58	-1.763
98	100	Biased	15.295	13.501	-1.794
99	100	Unbiased	15.536	14.978	-0.558
100	100	Unbiased	15.442	14.888	-0.554
101	100	Unbiased	15.398	14.876	-0.522
102	0	Correlation	15.191	15.17	-0.021
103	0	Correlation	15.247	15.201	-0.046

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	15.191	15.219	15.247	0.039598	15.17	15.186	15.201	0.02192	-0.046	-0.0335	-0.021	0.017678
50	15.316	15.419	15.562	0.083288	13.992	14.519	15.205	0.54388	-1.343	-0.90043	-0.319	0.52849
100	15.295	15.435	15.597	0.11483	13.501	14.268	14.978	0.7143	-1.81	-1.1668	-0.522	0.68183

Device Test: 18.41 WDO_RNMOS(Res_PD_WDOB/WDOB/7/3/0/0/2/@WDO_RNMOS)





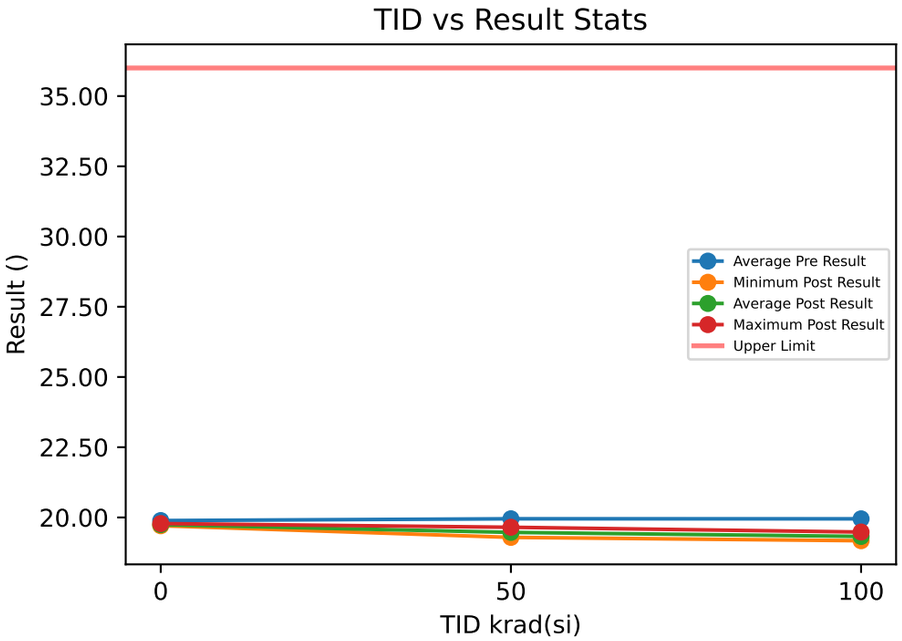
Test Results (Upper Limit = 36.0 ())

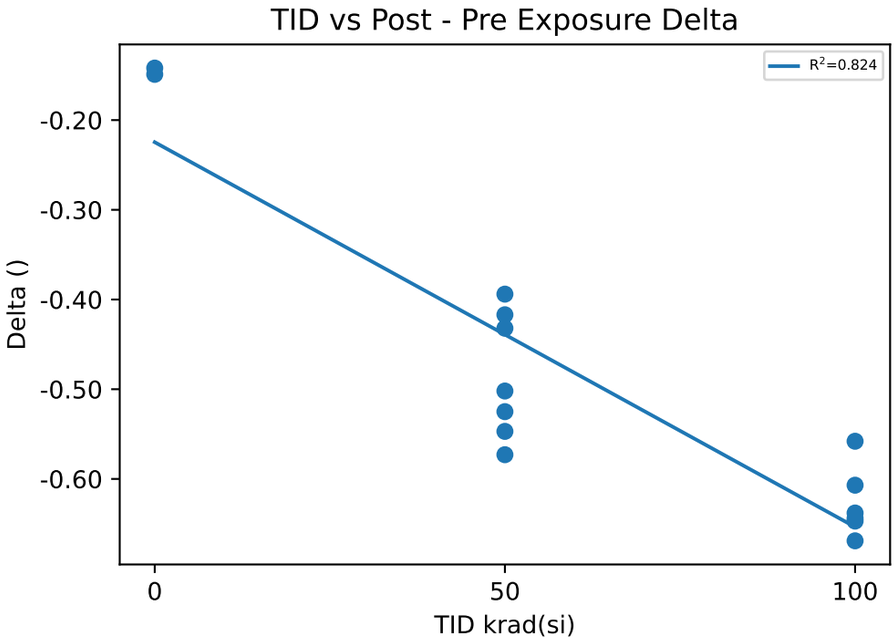
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	15.411	14.05	-1.361
89	50	Biased	15.486	14.092	-1.394
90	50	Biased	15.49	14.147	-1.343
92	50	Biased	15.63	14.273	-1.357
93	50	Unbiased	15.474	15.097	-0.377
94	50	Unbiased	15.593	15.198	-0.395
95	50	Unbiased	15.458	15.09	-0.368
96	100	Biased	15.707	13.862	-1.845
97	100	Biased	15.471	13.668	-1.803
98	100	Biased	15.422	13.601	-1.821
99	100	Unbiased	15.611	15.015	-0.596
100	100	Unbiased	15.609	15.002	-0.607
101	100	Unbiased	15.509	14.954	-0.555
102	0	Correlation	15.324	15.254	-0.07
103	0	Correlation	15.37	15.266	-0.104

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	15.324	15.347	15.37	0.032527	15.254	15.26	15.266	0.0084853	-0.104	-0.087	-0.07	0.024042
50	15.411	15.506	15.63	0.07741	14.05	14.564	15.198	0.53358	-1.394	-0.94214	-0.368	0.52612
100	15.422	15.555	15.707	0.10585	13.601	14.35	15.015	0.7066	-1.845	-1.2045	-0.555	0.67789

Device Test: 18.42 RESET_RNMOS(Res_PD_RESETB1/RESETB1/7/14/0/0/2/@RESET_RNMOS)





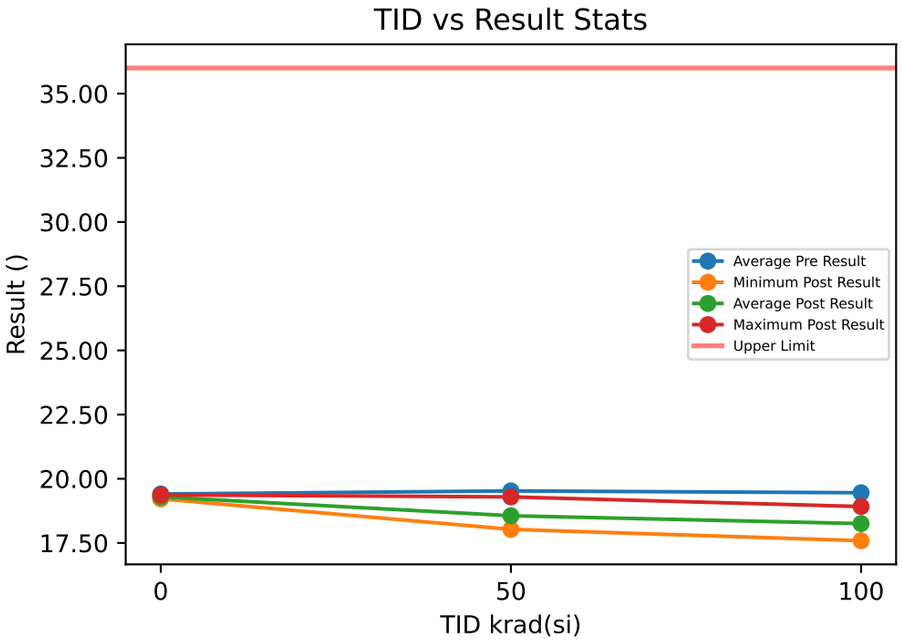
Test Results (Upper Limit = 36.0 ())

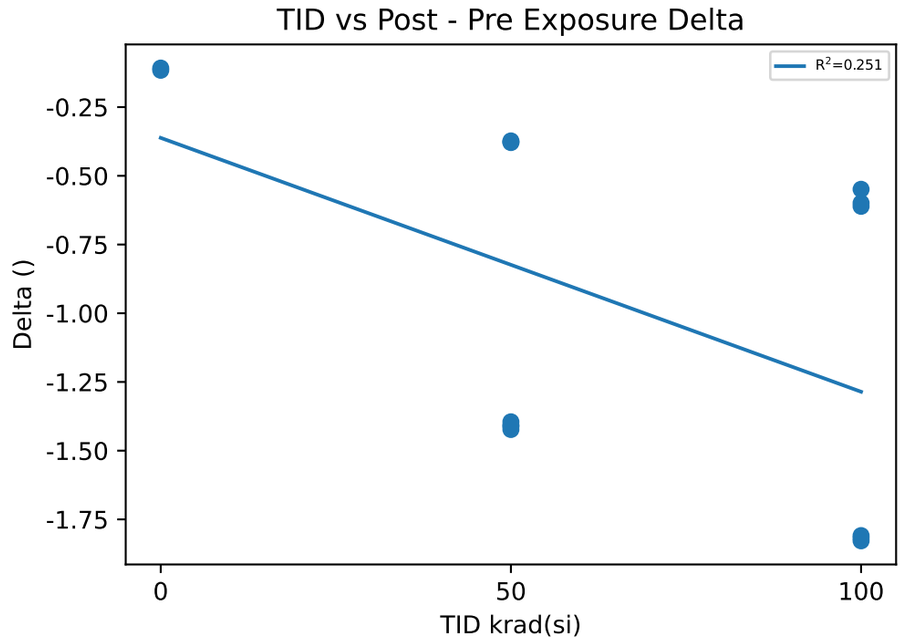
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.863	19.29	-0.573
89	50	Biased	19.959	19.434	-0.525
90	50	Biased	20.04	19.493	-0.547
92	50	Biased	19.838	19.336	-0.502
93	50	Unbiased	19.947	19.553	-0.394
94	50	Unbiased	20.082	19.65	-0.432
95	50	Unbiased	19.935	19.518	-0.417
96	100	Biased	20.046	19.408	-0.638
97	100	Biased	19.845	19.198	-0.647
98	100	Biased	19.84	19.171	-0.669
99	100	Unbiased	20.124	19.48	-0.644
100	100	Unbiased	19.919	19.312	-0.607
101	100	Unbiased	19.929	19.371	-0.558
102	0	Correlation	19.847	19.705	-0.142
103	0	Correlation	19.93	19.781	-0.149

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.847	19.889	19.93	0.05869	19.705	19.743	19.781	0.05374	-0.149	-0.1455	-0.142	0.0049497
50	19.838	19.952	20.082	0.087487	19.29	19.468	19.65	0.12499	-0.573	-0.48429	-0.394	0.069746
100	19.84	19.951	20.124	0.11315	19.171	19.323	19.48	0.12085	-0.669	-0.62717	-0.558	0.039331

Device Test: 18.43 RESET_RNMOS(Res_PD_RESETB2/RESETB2/7/14/0/0/2/@RESET_RNMOS)





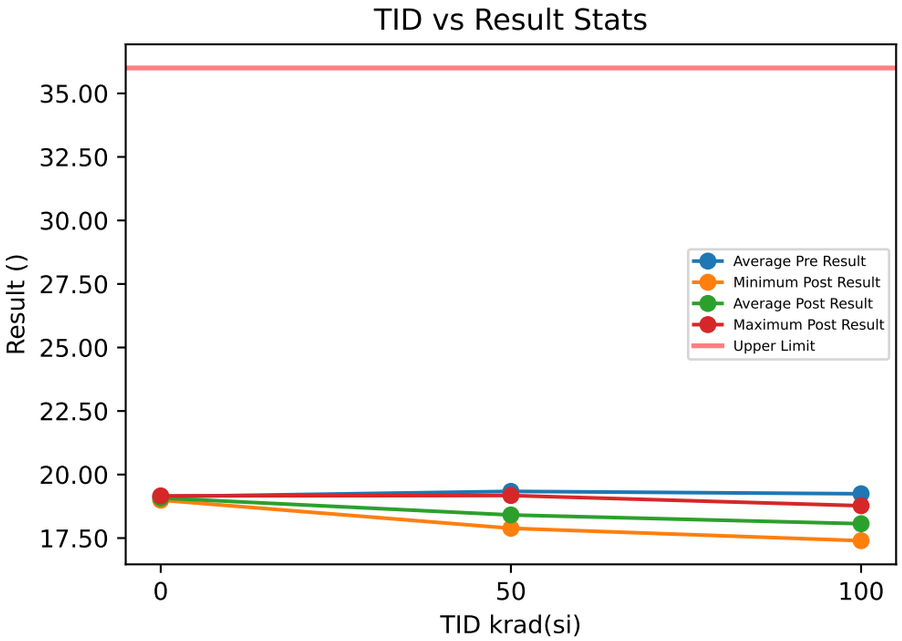
Test Results (Upper Limit = 36.0 ())

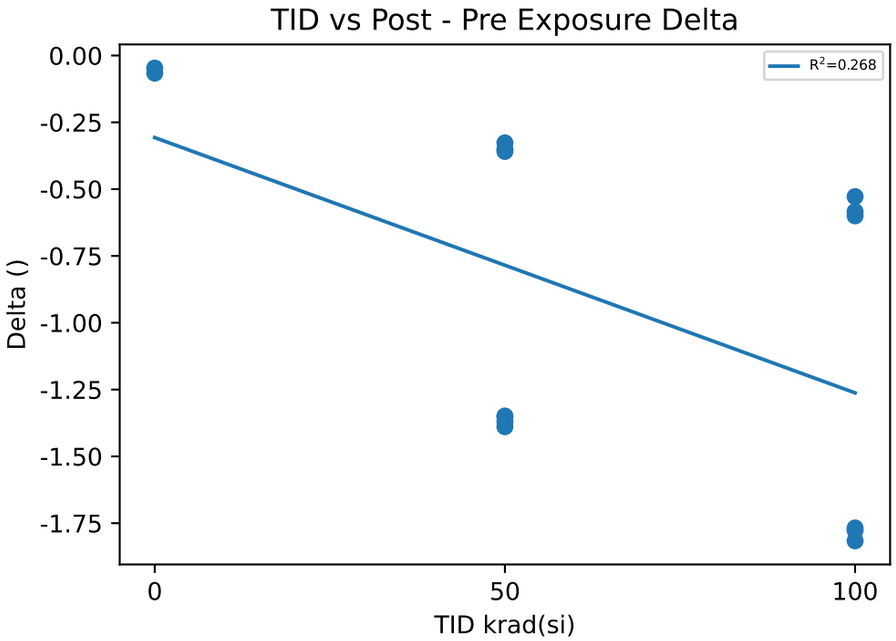
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.453	18.03	-1.423
89	50	Biased	19.517	18.122	-1.395
90	50	Biased	19.513	18.105	-1.408
92	50	Biased	19.702	18.291	-1.411
93	50	Unbiased	19.424	19.051	-0.373
94	50	Unbiased	19.673	19.294	-0.379
95	50	Unbiased	19.402	19.025	-0.377
96	100	Biased	19.487	17.678	-1.809
97	100	Biased	19.452	17.624	-1.828
98	100	Biased	19.405	17.587	-1.818
99	100	Unbiased	19.517	18.918	-0.599
100	100	Unbiased	19.497	18.886	-0.611
101	100	Unbiased	19.377	18.828	-0.549
102	0	Correlation	19.326	19.218	-0.108
103	0	Correlation	19.487	19.371	-0.116

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.326	19.407	19.487	0.11384	19.218	19.294	19.371	0.10819	-0.116	-0.112	-0.108	0.0056569
50	19.402	19.526	19.702	0.11828	18.03	18.56	19.294	0.53978	-1.423	-0.96657	-0.373	0.55218
100	19.377	19.456	19.517	0.055174	17.587	18.253	18.918	0.6846	-1.828	-1.2023	-0.549	0.67514

Device Test: 18.44 RESET_RNMOS(Res_PD_RESETB3/RESETB3/7/14/0/0/2/@RESET_RNMOS)





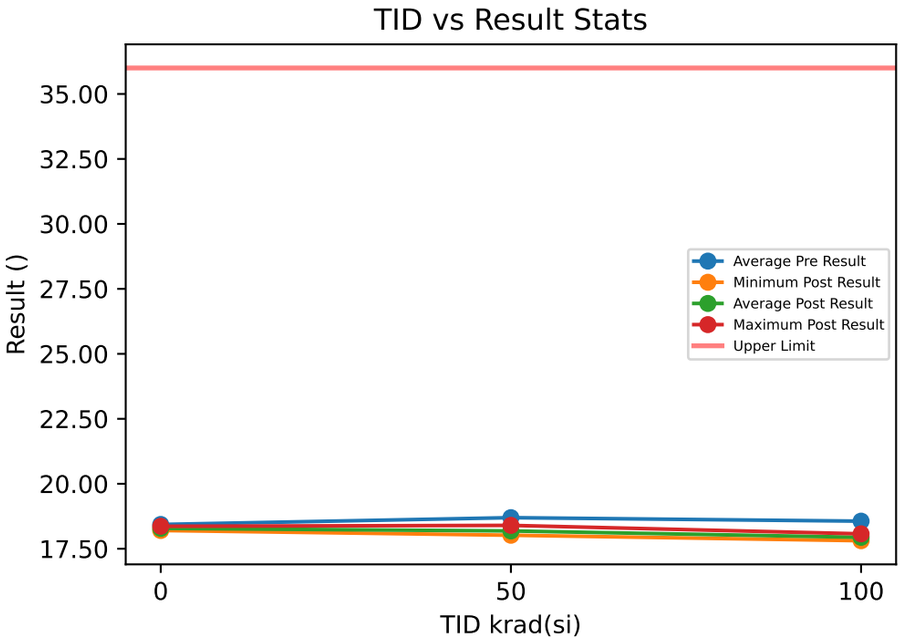
Test Results (Upper Limit = 36.0 ())

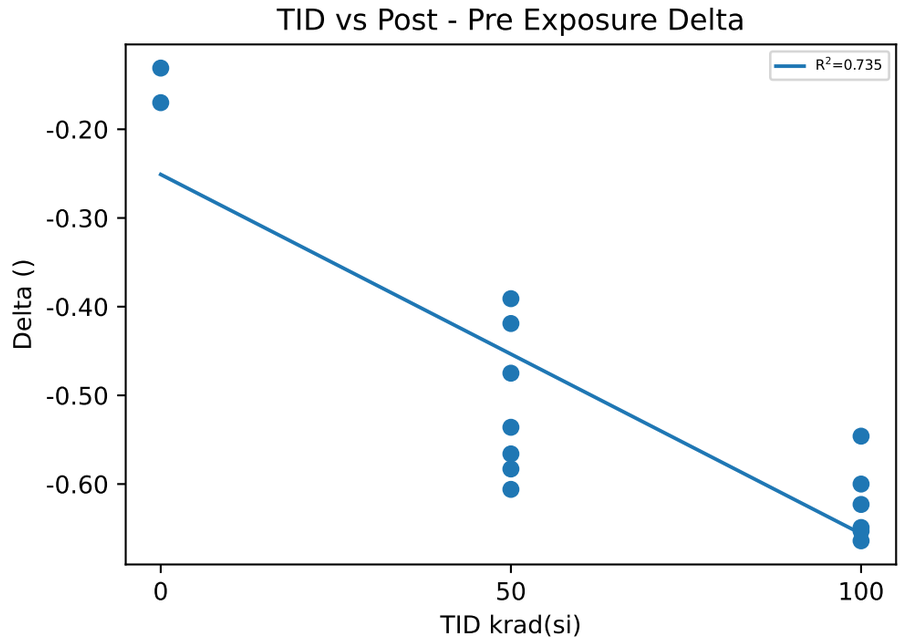
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.274	17.885	-1.389
89	50	Biased	19.352	18.001	-1.351
90	50	Biased	19.323	17.974	-1.349
92	50	Biased	19.511	18.141	-1.37
93	50	Unbiased	19.224	18.873	-0.351
94	50	Unbiased	19.502	19.175	-0.327
95	50	Unbiased	19.179	18.82	-0.359
96	100	Biased	19.318	17.55	-1.768
97	100	Biased	19.187	17.41	-1.777
98	100	Biased	19.212	17.396	-1.816
99	100	Unbiased	19.357	18.773	-0.584
100	100	Unbiased	19.215	18.615	-0.6
101	100	Unbiased	19.171	18.643	-0.528
102	0	Correlation	19.039	18.992	-0.047
103	0	Correlation	19.226	19.16	-0.066

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.039	19.133	19.226	0.13223	18.992	19.076	19.16	0.11879	-0.066	-0.0565	-0.047	0.013435
50	19.179	19.338	19.511	0.12885	17.885	18.41	19.175	0.52806	-1.389	-0.928	-0.327	0.54497
100	19.171	19.243	19.357	0.075743	17.396	18.064	18.773	0.67523	-1.816	-1.1788	-0.528	0.66684

Device Test: 18.45 RESET_RNMOS(Res_PD_RESETB4/RESETB4/7/14/0/0/2/@RESET_RNMOS)





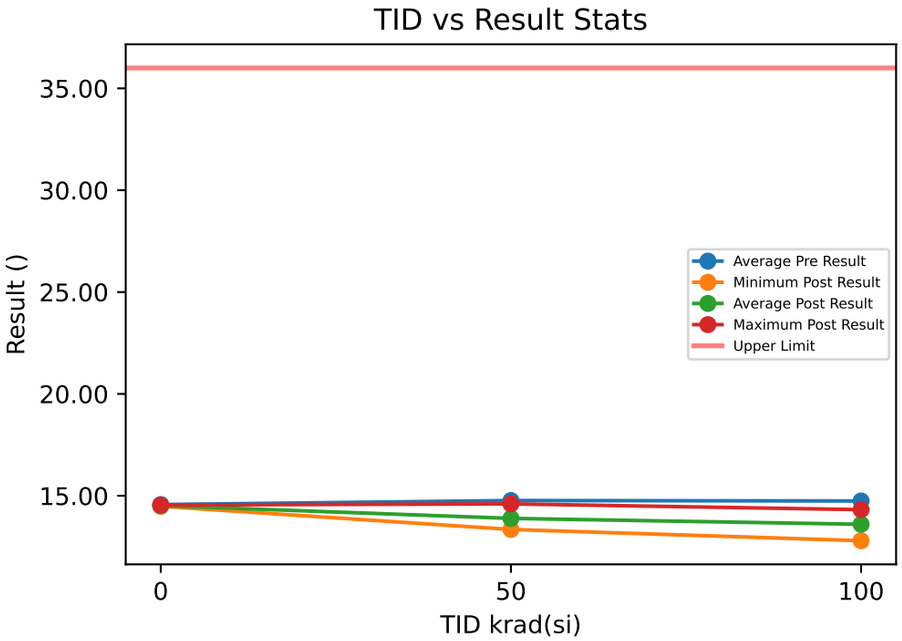
Test Results (Upper Limit = 36.0 ())

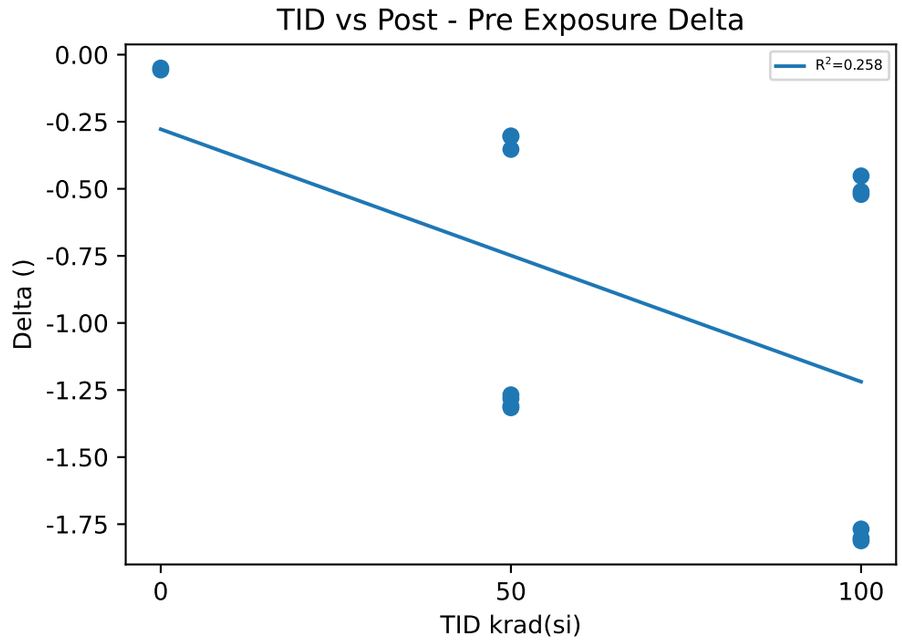
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	18.603	18.02	-0.583
89	50	Biased	18.648	18.112	-0.536
90	50	Biased	18.712	18.146	-0.566
92	50	Biased	18.989	18.383	-0.606
93	50	Unbiased	18.569	18.15	-0.419
94	50	Unbiased	18.874	18.399	-0.475
95	50	Unbiased	18.478	18.087	-0.391
96	100	Biased	18.711	18.047	-0.664
97	100	Biased	18.525	17.876	-0.649
98	100	Biased	18.462	17.809	-0.653
99	100	Unbiased	18.697	18.074	-0.623
100	100	Unbiased	18.512	17.912	-0.6
101	100	Unbiased	18.465	17.919	-0.546
102	0	Correlation	18.334	18.203	-0.131
103	0	Correlation	18.535	18.365	-0.17

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.334	18.434	18.535	0.14213	18.203	18.284	18.365	0.11455	-0.17	-0.1505	-0.131	0.027577
50	18.478	18.696	18.989	0.17907	18.02	18.185	18.399	0.14714	-0.606	-0.51086	-0.391	0.083685
100	18.462	18.562	18.711	0.11288	17.809	17.939	18.074	0.10187	-0.664	-0.6225	-0.546	0.044076

Device Test: 18.46 PWRGD_RNMOS(Res_PD_PWRDG/PWRGD/7/14/0/0/2/@PWRGD_RNMOS)





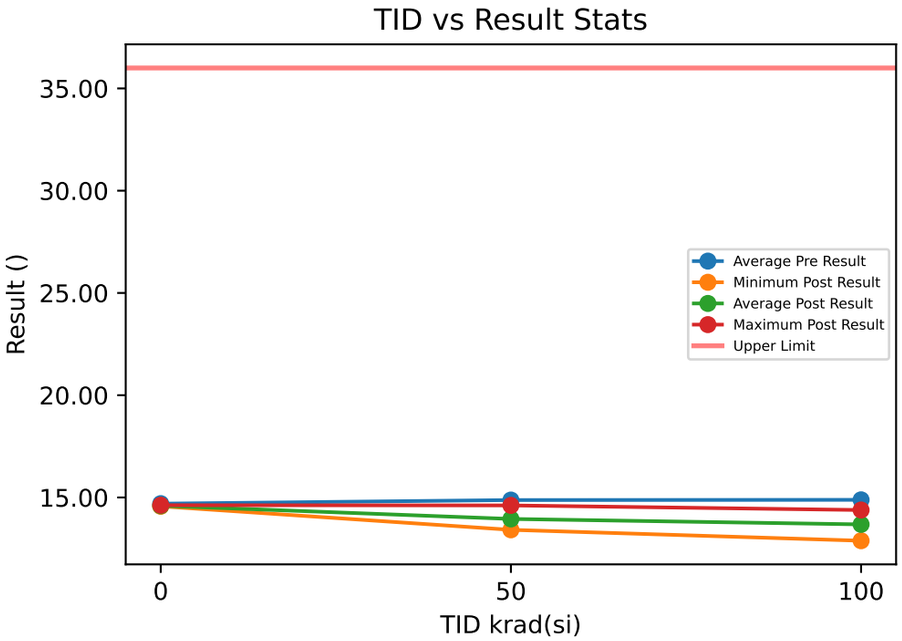
Test Results (Upper Limit = 36.0 ())

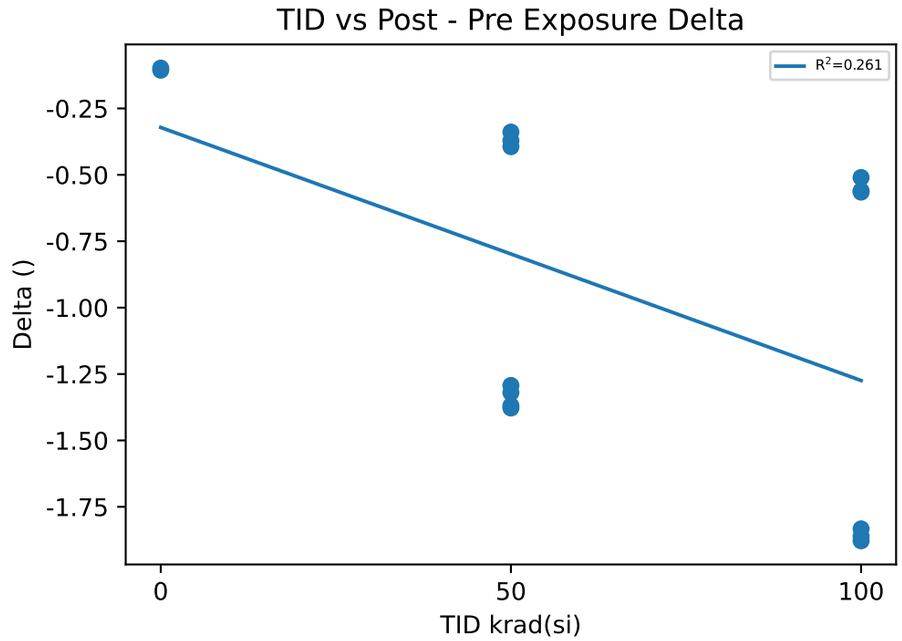
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	14.663	13.347	-1.316
89	50	Biased	14.755	13.445	-1.31
90	50	Biased	14.779	13.511	-1.268
92	50	Biased	14.841	13.559	-1.282
93	50	Unbiased	14.674	14.369	-0.305
94	50	Unbiased	14.955	14.602	-0.353
95	50	Unbiased	14.699	14.396	-0.303
96	100	Biased	14.906	13.104	-1.802
97	100	Biased	14.652	12.884	-1.768
98	100	Biased	14.606	12.794	-1.812
99	100	Unbiased	14.829	14.319	-0.51
100	100	Unbiased	14.773	14.252	-0.521
101	100	Unbiased	14.702	14.25	-0.452
102	0	Correlation	14.534	14.484	-0.05
103	0	Correlation	14.603	14.546	-0.057

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.534	14.569	14.603	0.04879	14.484	14.515	14.546	0.043841	-0.057	-0.0535	-0.05	0.0049497
50	14.663	14.767	14.955	0.10424	13.347	13.89	14.602	0.53828	-1.316	-0.87671	-0.303	0.52095
100	14.606	14.745	14.906	0.11276	12.794	13.601	14.319	0.7447	-1.812	-1.1442	-0.452	0.71239

Device Test: 18.47 WDO_RNMOS(Res_PD_WDOB/WDOB/7/14/0/0/2/@WDO_RNMOS)





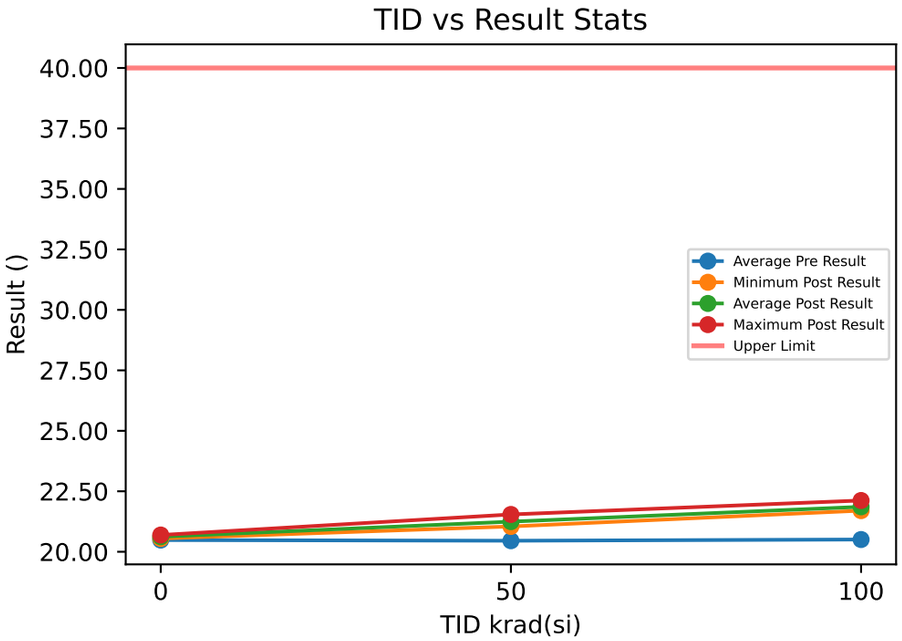
Test Results (Upper Limit = 36.0 ())

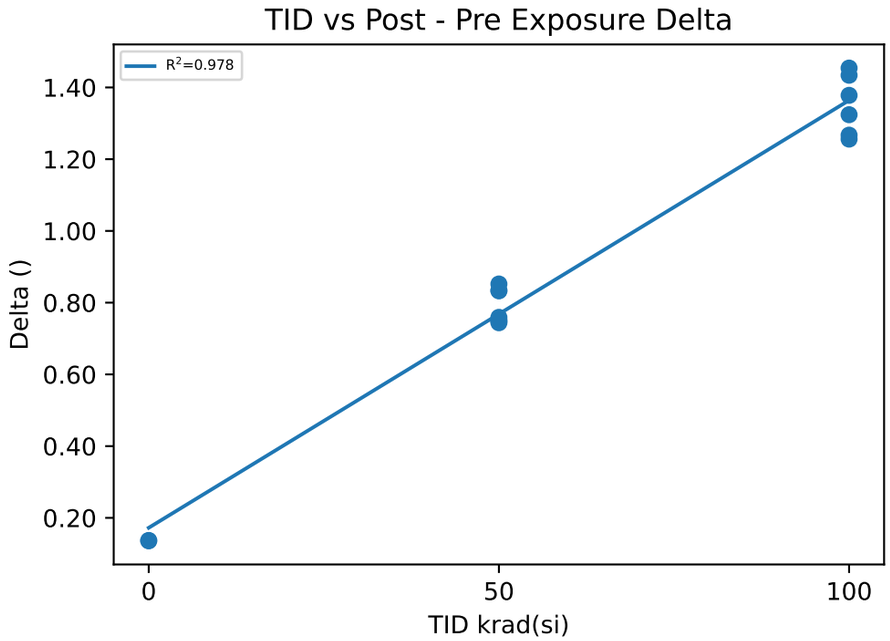
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	14.796	13.418	-1.378
89	50	Biased	14.847	13.478	-1.369
90	50	Biased	14.85	13.557	-1.293
92	50	Biased	14.992	13.672	-1.32
93	50	Unbiased	14.803	14.464	-0.339
94	50	Unbiased	15.006	14.612	-0.394
95	50	Unbiased	14.818	14.447	-0.371
96	100	Biased	15.042	13.164	-1.878
97	100	Biased	14.788	12.955	-1.833
98	100	Biased	14.746	12.885	-1.861
99	100	Unbiased	14.94	14.375	-0.565
100	100	Unbiased	14.946	14.386	-0.56
101	100	Unbiased	14.844	14.334	-0.51
102	0	Correlation	14.667	14.569	-0.098
103	0	Correlation	14.728	14.622	-0.106

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.667	14.697	14.728	0.043134	14.569	14.596	14.622	0.037477	-0.106	-0.102	-0.098	0.0056569
50	14.796	14.873	15.006	0.08842	13.418	13.95	14.612	0.53025	-1.378	-0.92343	-0.339	0.52058
100	14.746	14.884	15.042	0.11118	12.885	13.683	14.386	0.75273	-1.878	-1.2012	-0.51	0.7192

Device Test: 18.5 WDO_RPMOS_LOW_V(Res_PU_WDOB/WDOB/1.6/3/0/0/2/@WDO_RPMOS_LOW_V)





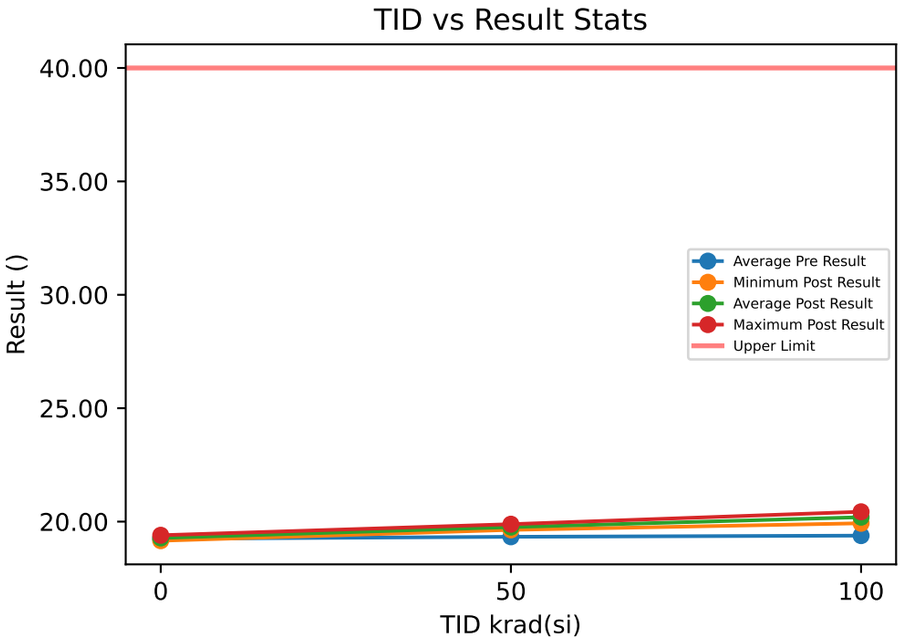
Test Results (Upper Limit = 40.0 ())

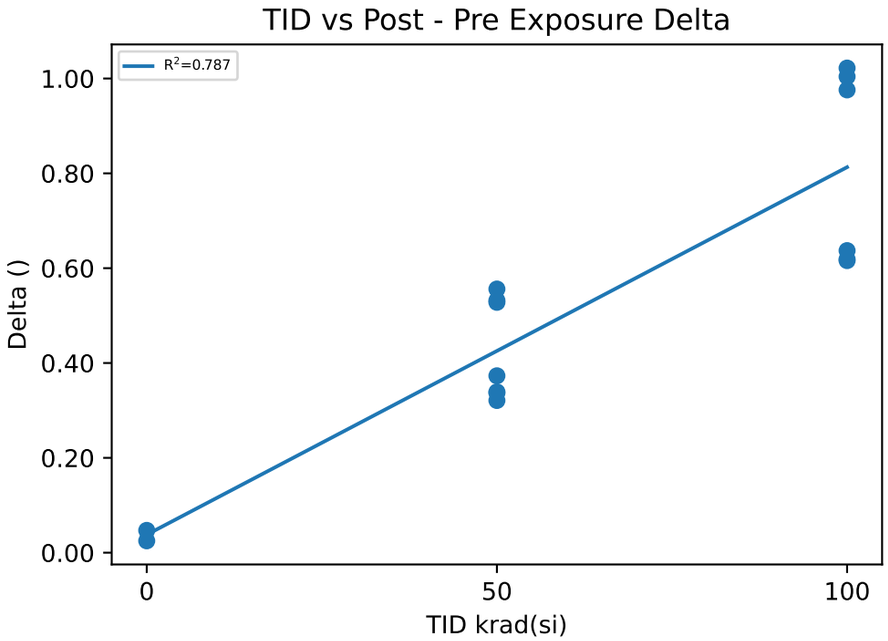
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	20.319	21.067	0.748
89	50	Biased	20.285	21.119	0.834
90	50	Biased	20.432	21.265	0.833
92	50	Biased	20.69	21.542	0.852
93	50	Unbiased	20.621	21.38	0.759
94	50	Unbiased	20.295	21.046	0.751
95	50	Unbiased	20.552	21.296	0.744
96	100	Biased	20.422	21.8	1.378
97	100	Biased	20.665	22.119	1.454
98	100	Biased	20.459	21.893	1.434
99	100	Unbiased	20.433	21.7	1.267
100	100	Unbiased	20.502	21.758	1.256
101	100	Unbiased	20.553	21.877	1.324
102	0	Correlation	20.412	20.548	0.136
103	0	Correlation	20.555	20.692	0.137

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.412	20.483	20.555	0.10112	20.548	20.62	20.692	0.10182	0.136	0.1365	0.137	0.00070711
50	20.285	20.456	20.69	0.16618	21.046	21.245	21.542	0.18101	0.744	0.78871	0.852	0.048269
100	20.422	20.506	20.665	0.09176	21.7	21.858	22.119	0.14699	1.256	1.3522	1.454	0.0837

Device Test: 18.6 RESET_RPMOS_LOW_V(Res_PU_RESETB1/RESETB1/1.6/14/0/0/2/@RESET_RPMOS_LOW_V)





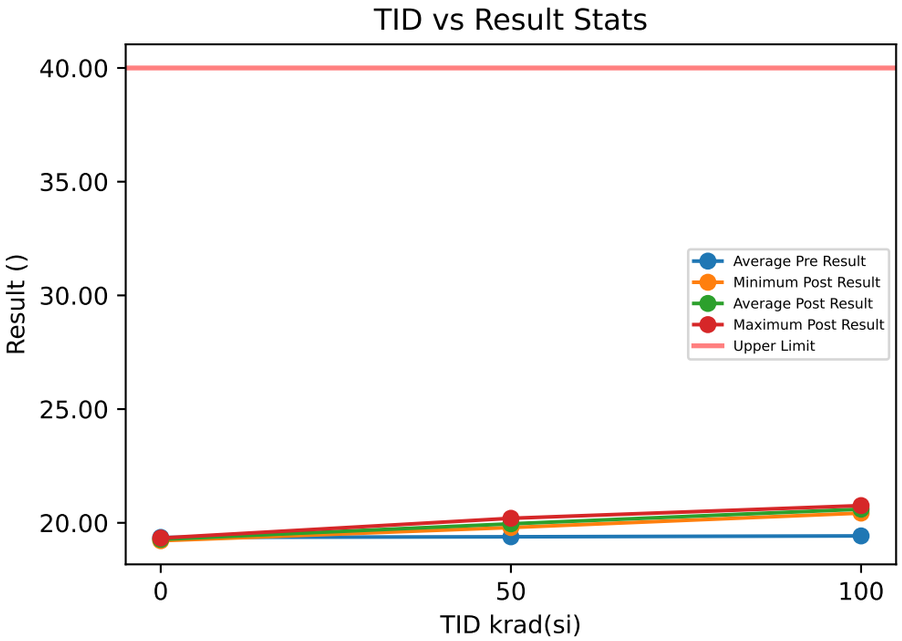
Test Results (Upper Limit = 40.0 ())

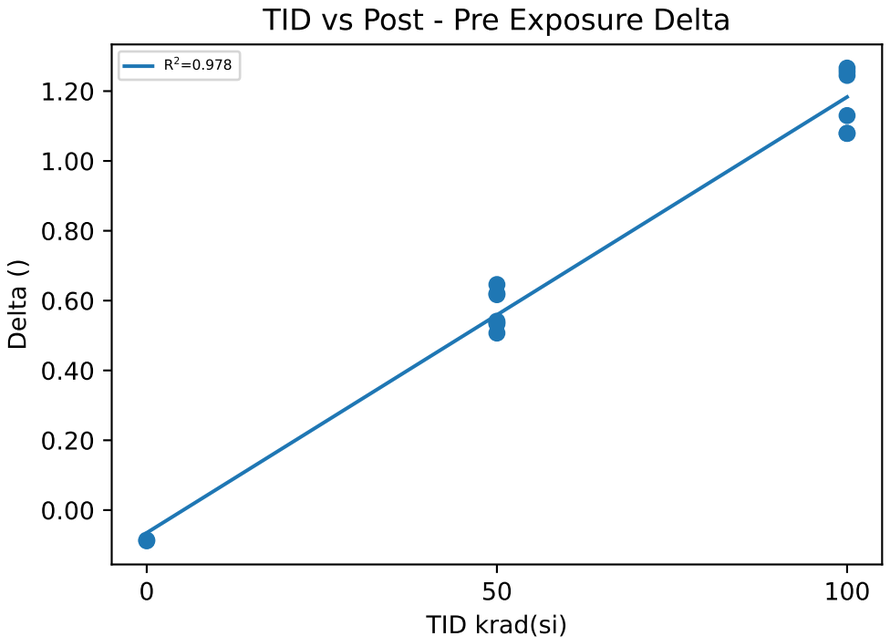
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.419	19.74	0.321
89	50	Biased	19.299	19.636	0.337
90	50	Biased	19.307	19.646	0.339
92	50	Biased	19.514	19.887	0.373
93	50	Unbiased	19.315	19.871	0.556
94	50	Unbiased	19.292	19.82	0.528
95	50	Unbiased	19.174	19.706	0.532
96	100	Biased	19.4	20.019	0.619
97	100	Biased	19.368	20.005	0.637
98	100	Biased	19.311	19.927	0.616
99	100	Unbiased	19.379	20.355	0.976
100	100	Unbiased	19.43	20.434	1.004
101	100	Unbiased	19.408	20.43	1.022
102	0	Correlation	19.111	19.158	0.047
103	0	Correlation	19.374	19.399	0.025

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.111	19.242	19.374	0.18597	19.158	19.279	19.399	0.17041	0.025	0.036	0.047	0.015556
50	19.174	19.331	19.514	0.10744	19.636	19.758	19.887	0.10305	0.321	0.42657	0.556	0.10635
100	19.311	19.383	19.43	0.041346	19.927	20.195	20.434	0.23531	0.616	0.81233	1.022	0.20695

Device Test: 18.7 RESET_RPMOS_LOW_V(Res_PU_RESETB2/RESETB2/1.6/14/0/0/2/@RESET_RPMOS_LOW_V)





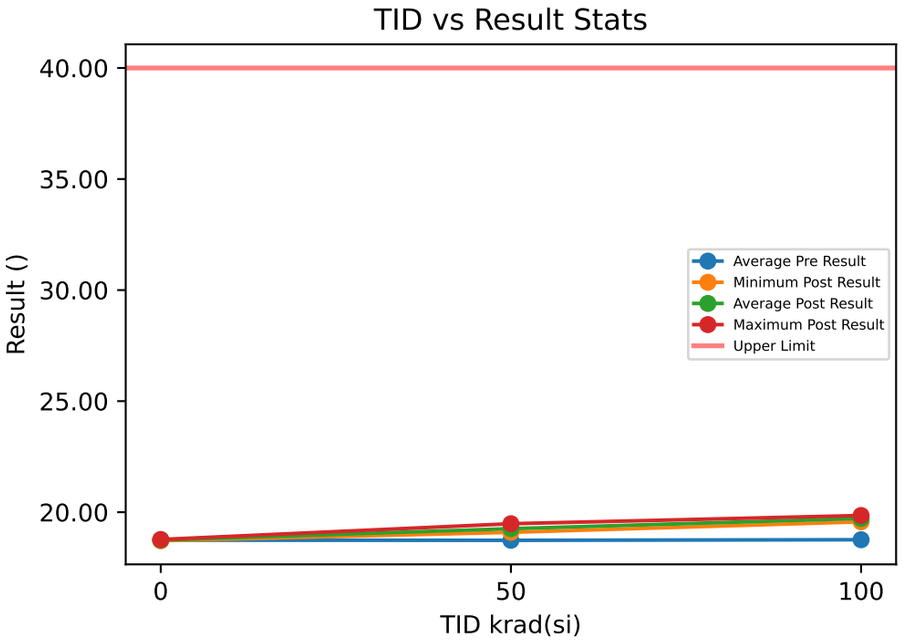
Test Results (Upper Limit = 40.0 ())

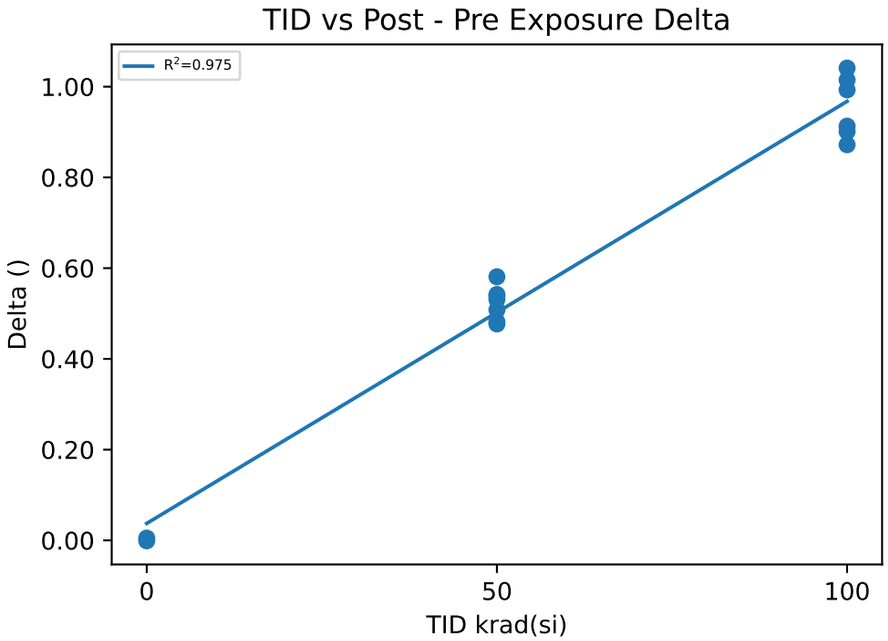
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19.324	19.861	0.537
89	50	Biased	19.243	19.86	0.617
90	50	Biased	19.409	20.029	0.62
92	50	Biased	19.553	20.199	0.646
93	50	Unbiased	19.5	20.041	0.541
94	50	Unbiased	19.286	19.793	0.507
95	50	Unbiased	19.386	19.919	0.533
96	100	Biased	19.409	20.654	1.245
97	100	Biased	19.491	20.757	1.266
98	100	Biased	19.382	20.638	1.256
99	100	Unbiased	19.349	20.428	1.079
100	100	Unbiased	19.509	20.588	1.079
101	100	Unbiased	19.406	20.536	1.13
102	0	Correlation	19.301	19.213	-0.088
103	0	Correlation	19.416	19.33	-0.086

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.301	19.358	19.416	0.081317	19.213	19.271	19.33	0.082731	-0.088	-0.087	-0.086	0.0014142
50	19.243	19.386	19.553	0.11233	19.793	19.957	20.199	0.1401	0.507	0.57157	0.646	0.054369
100	19.349	19.424	19.509	0.062692	20.428	20.6	20.757	0.1121	1.079	1.1758	1.266	0.08966

Device Test: 18.8 RESET_RPMOS_LOW_V(Res_PU_RESETB3/RESETB3/1.6/14/0/0/2/@RESET_RPMOS_LOW_V)





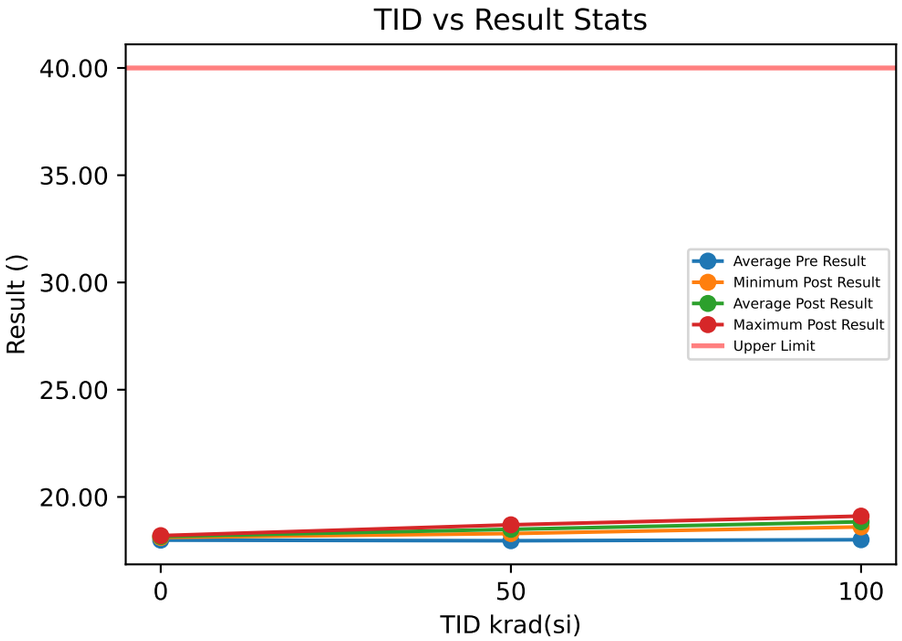
Test Results (Upper Limit = 40.0 ())

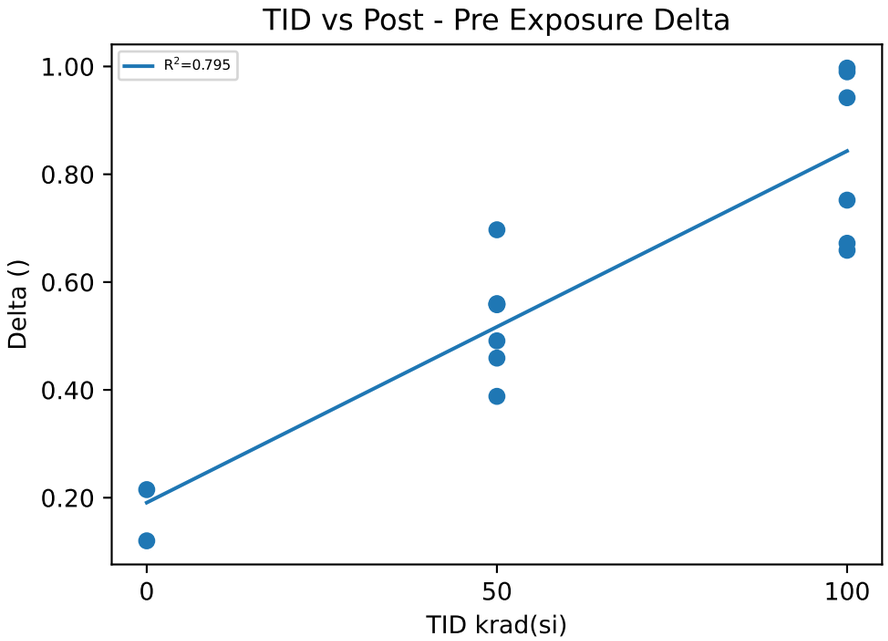
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	18.703	19.234	0.531
89	50	Biased	18.556	19.094	0.538
90	50	Biased	18.724	19.266	0.542
92	50	Biased	18.9	19.481	0.581
93	50	Unbiased	18.844	19.352	0.508
94	50	Unbiased	18.623	19.105	0.482
95	50	Unbiased	18.797	19.274	0.477
96	100	Biased	18.719	19.734	1.015
97	100	Biased	18.81	19.851	1.041
98	100	Biased	18.696	19.689	0.993
99	100	Unbiased	18.695	19.567	0.872
100	100	Unbiased	18.784	19.685	0.901
101	100	Unbiased	18.86	19.773	0.913
102	0	Correlation	18.711	18.716	0.005
103	0	Correlation	18.772	18.771	-0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.711	18.741	18.772	0.043134	18.716	18.744	18.771	0.038891	-0.001	0.002	0.005	0.0042426
50	18.556	18.735	18.9	0.12157	19.094	19.258	19.481	0.13526	0.477	0.52271	0.581	0.036596
100	18.695	18.761	18.86	0.067934	19.567	19.716	19.851	0.09559	0.872	0.95583	1.041	0.069289

Device Test: 18.9 RESET_RPMOS_LOW_V(Res_PU_RESETB4/RESETB4/1.6/14/0/0/2/@RESET_RPMOS_LOW_V)





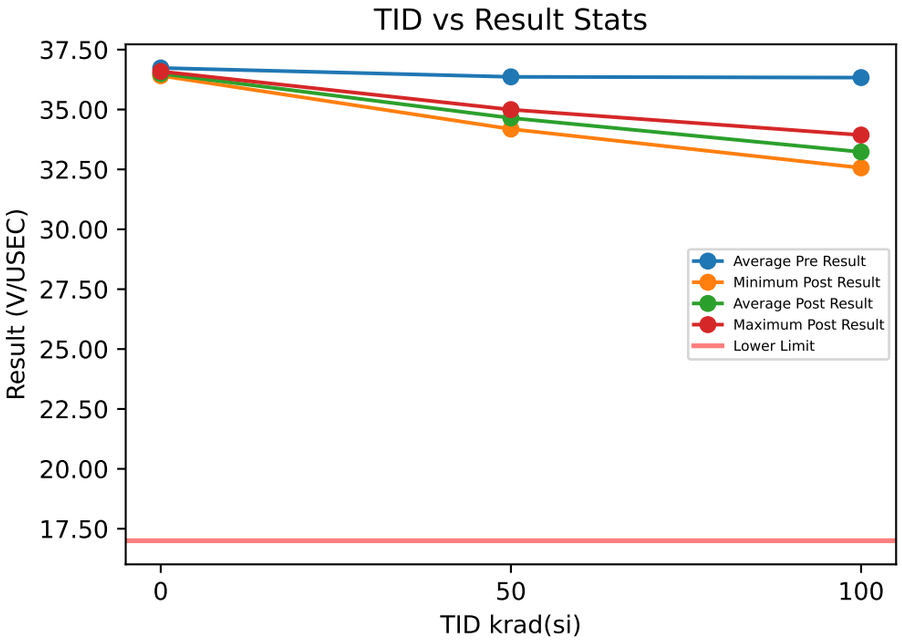
Test Results (Upper Limit = 40.0 ())

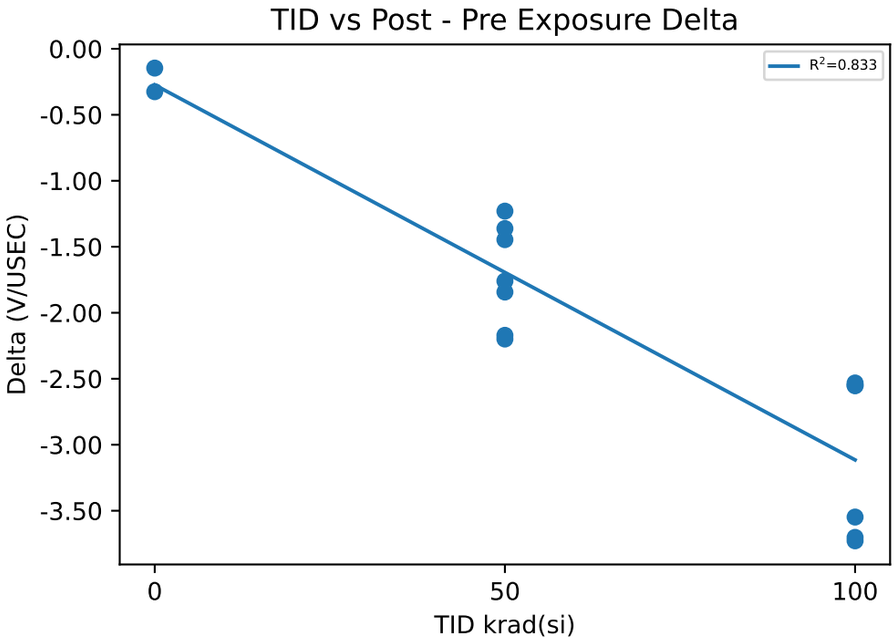
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	17.918	18.377	0.459
89	50	Biased	17.736	18.294	0.558
90	50	Biased	17.887	18.378	0.491
92	50	Biased	18.196	18.584	0.388
93	50	Unbiased	18.141	18.701	0.56
94	50	Unbiased	17.778	18.475	0.697
95	50	Unbiased	18.063	18.622	0.559
96	100	Biased	17.851	18.603	0.752
97	100	Biased	18.09	18.749	0.659
98	100	Biased	17.992	18.664	0.672
99	100	Unbiased	17.894	18.884	0.99
100	100	Unbiased	18.1	19.042	0.942
101	100	Unbiased	18.11	19.107	0.997
102	0	Correlation	17.897	18.112	0.215
103	0	Correlation	18.077	18.197	0.12

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.897	17.987	18.077	0.12728	18.112	18.154	18.197	0.060104	0.12	0.1675	0.215	0.067175
50	17.736	17.96	18.196	0.1777	18.294	18.49	18.701	0.14985	0.388	0.53029	0.697	0.097587
100	17.851	18.006	18.11	0.11267	18.603	18.841	19.107	0.20467	0.659	0.83533	0.997	0.15884

Device Test: 19.0 RESET_SLEW_RATE_RISE(tsr_RESETB1_Rising/RESETB1/1.6/3/0/0/0/@RESET_SLEW_RATE_RISE)





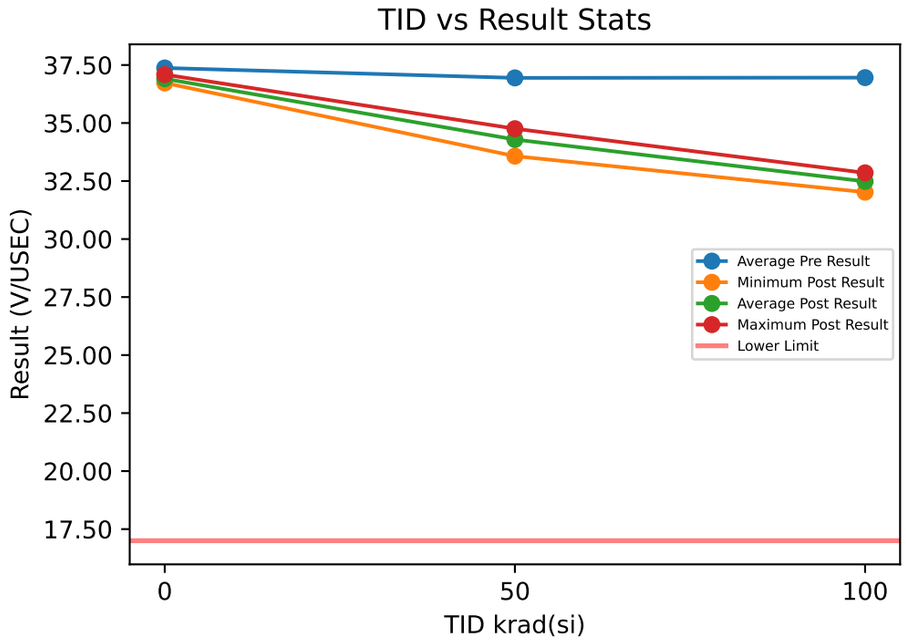
Test Results (Lower Limit = 17.0 (V/USEC))

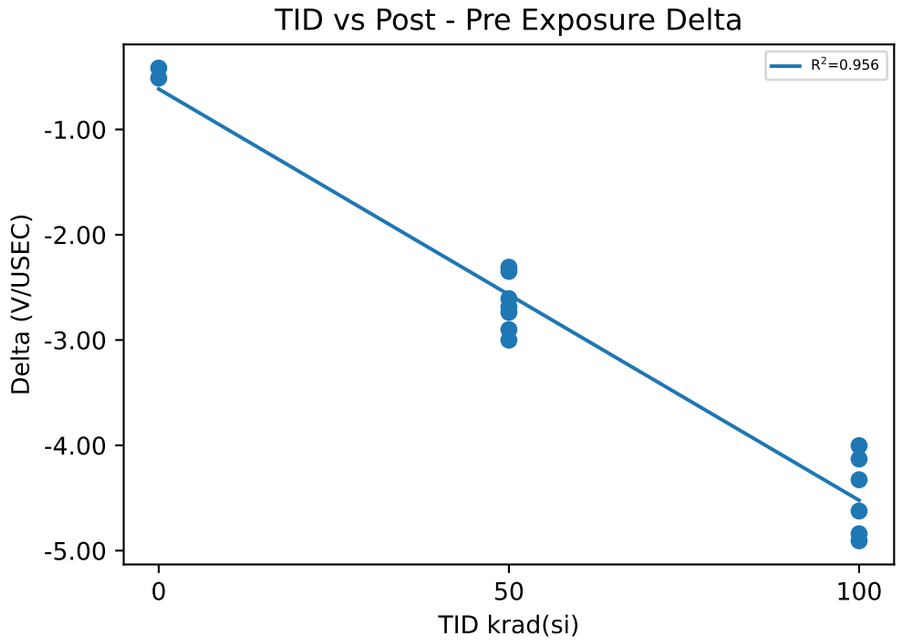
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	36.225	34.995	-1.23
89	50	Biased	36.419	34.973	-1.446
90	50	Biased	36.22	34.858	-1.362
92	50	Biased	35.945	34.185	-1.76
93	50	Unbiased	36.506	34.335	-2.171
94	50	Unbiased	36.274	34.431	-1.843
95	50	Unbiased	36.954	34.755	-2.199
96	100	Biased	36.384	33.831	-2.553
97	100	Biased	36.467	33.935	-2.532
98	100	Biased	36.3	33.75	-2.55
99	100	Unbiased	36.267	32.565	-3.702
100	100	Unbiased	36.395	32.667	-3.728
101	100	Unbiased	36.179	32.631	-3.548
102	0	Correlation	36.912	36.587	-0.325
103	0	Correlation	36.556	36.41	-0.146

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	36.556	36.734	36.912	0.25173	36.41	36.498	36.587	0.12516	-0.325	-0.2355	-0.146	0.12657
50	35.945	36.363	36.954	0.31491	34.185	34.647	34.995	0.32686	-2.199	-1.7159	-1.23	0.38574
100	36.179	36.332	36.467	0.10349	32.565	33.23	33.935	0.67032	-3.728	-3.1022	-2.532	0.61348

Device Test: 19.1 RESET_SLEW_RATE_RISE(tsr_RESETB2_Rising/RESETB2/1.6/3/0/0/0/@RESET_SLEW_RATE_RISE)





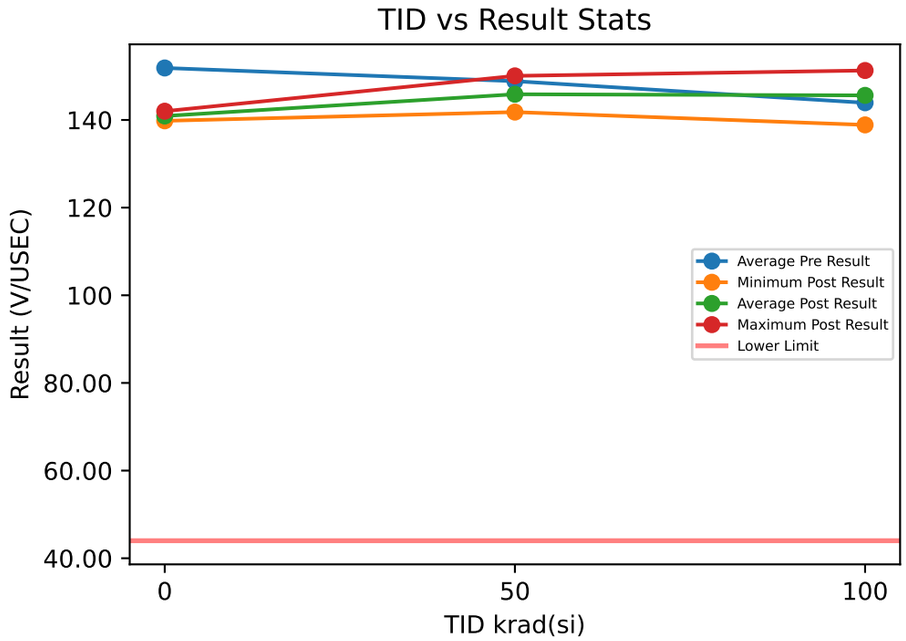
Test Results (Lower Limit = 17.0 (V/USEC))

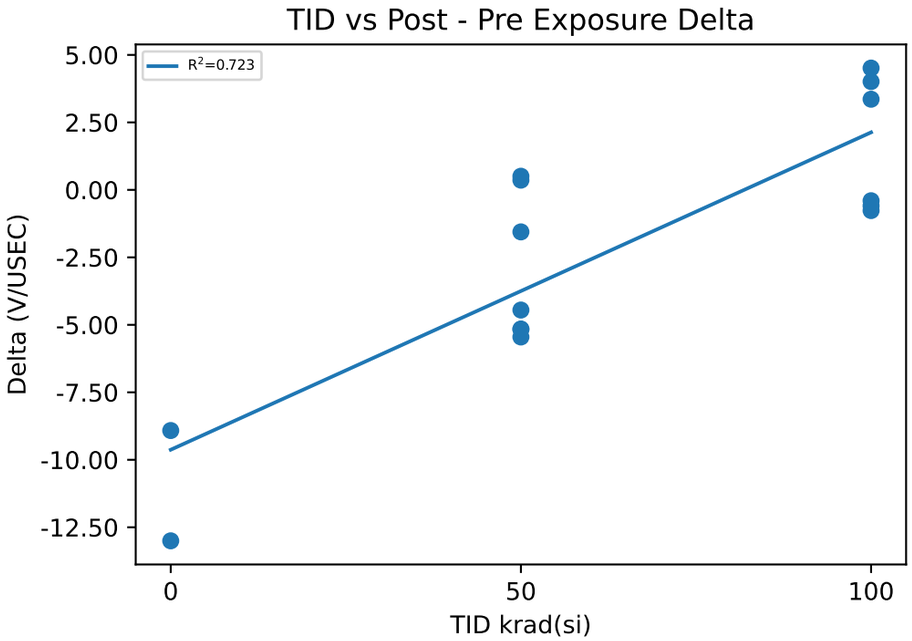
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	37.132	34.395	-2.737
89	50	Biased	36.898	34.212	-2.686
90	50	Biased	36.899	33.998	-2.901
92	50	Biased	36.575	33.574	-3.001
93	50	Unbiased	36.741	34.393	-2.348
94	50	Unbiased	37.363	34.756	-2.607
95	50	Unbiased	37.009	34.701	-2.308
96	100	Biased	37.198	32.291	-4.907
97	100	Biased	36.644	32.02	-4.624
98	100	Biased	37.038	32.198	-4.84
99	100	Unbiased	36.82	32.817	-4.003
100	100	Unbiased	36.857	32.727	-4.13
101	100	Unbiased	37.18	32.853	-4.327
102	0	Correlation	37.24	36.728	-0.512
103	0	Correlation	37.505	37.088	-0.417

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	37.24	37.373	37.505	0.18738	36.728	36.908	37.088	0.25456	-0.512	-0.4645	-0.417	0.067175
50	36.575	36.945	37.363	0.25711	33.574	34.29	34.756	0.41063	-3.001	-2.6554	-2.308	0.25977
100	36.644	36.956	37.198	0.21959	32.02	32.484	32.853	0.35789	-4.907	-4.4718	-4.003	0.37569

Device Test: 19.10 PWRGD_SLEW_RATE_FALL(tsr_PWRGD_Falling/PWRGD/1.6/3/0/0/0/@PWRGD_SLEW_RATE_FALL)





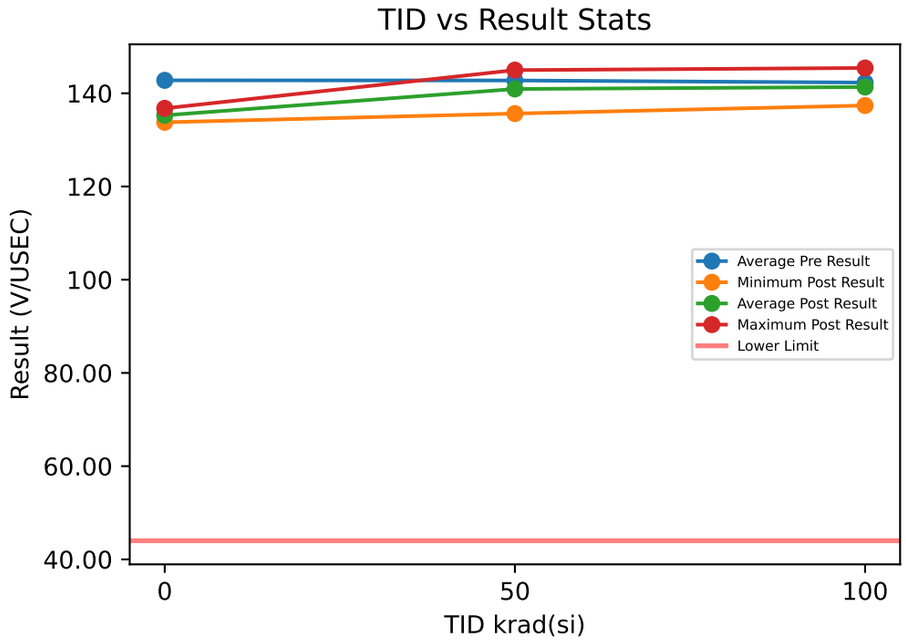
Test Results (Lower Limit = 44.0 (V/USEC))

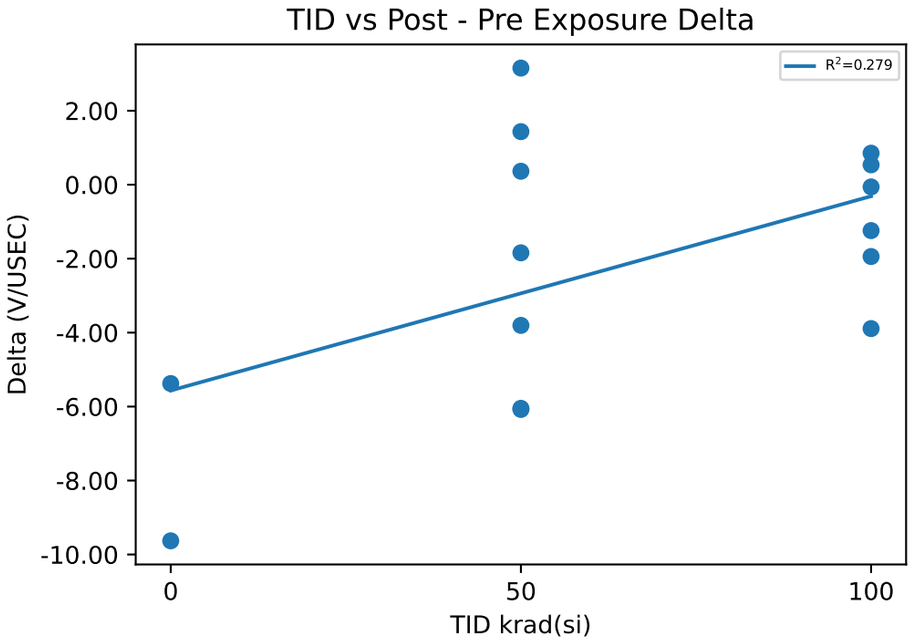
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	149.78	144.62	-5.168
89	50	Biased	149.7	150.06	0.36
90	50	Biased	146.25	141.8	-4.452
92	50	Biased	145	145.5	0.505
93	50	Unbiased	151.86	146.71	-5.155
94	50	Unbiased	149.16	147.61	-1.557
95	50	Unbiased	150.22	144.77	-5.45
96	100	Biased	148.87	148.28	-0.591
97	100	Biased	145.49	148.85	3.358
98	100	Biased	147.28	151.29	4.012
99	100	Unbiased	139.65	138.88	-0.767
100	100	Unbiased	141.07	140.67	-0.403
101	100	Unbiased	141.19	145.7	4.512
102	0	Correlation	152.81	139.81	-13.002
103	0	Correlation	150.92	142	-8.916

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	150.92	151.86	152.81	1.3371	139.81	140.9	142	1.5521	-13.002	-10.959	-8.916	2.8892
50	145	148.85	151.86	2.3885	141.8	145.87	150.06	2.6068	-5.45	-2.9881	0.505	2.6805
100	139.65	143.92	148.87	3.7966	138.88	145.61	151.29	4.8905	-0.767	1.6868	4.512	2.5202

Device Test: 19.11 WDO_SLEW_RATE_FALL(tsr_WDOB_Falling/WDOB/1.6/3/0/0/0/@WDO_SLEW_RATE_FALL)





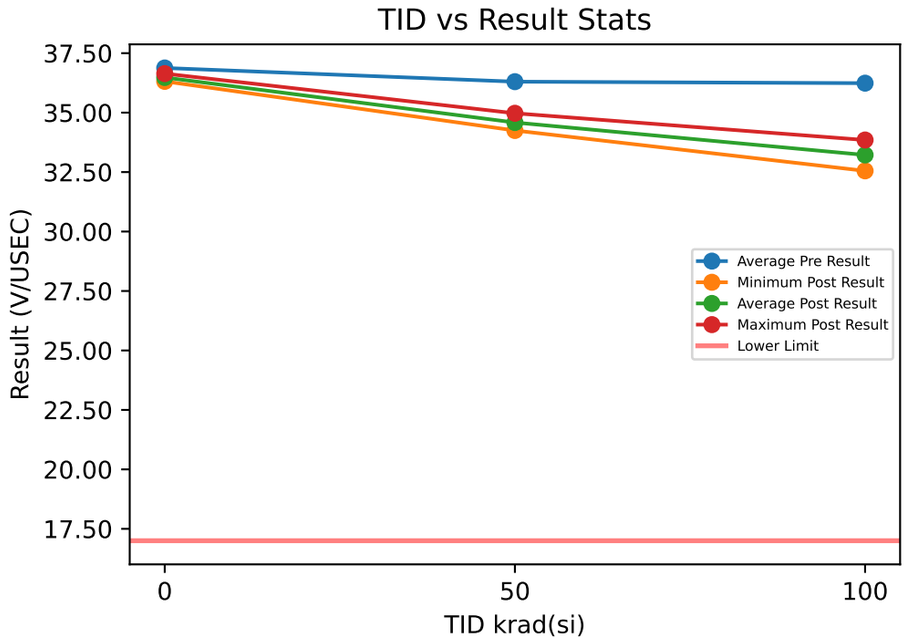
Test Results (Lower Limit = 44.0 (V/USEC))

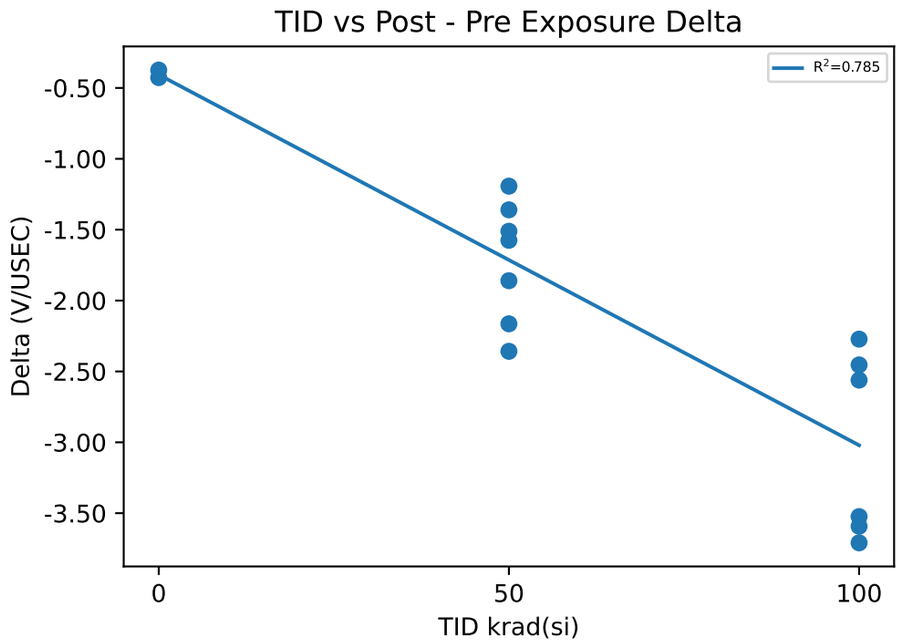
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	138.76	140.19	1.435
89	50	Biased	141.82	144.97	3.154
90	50	Biased	144.12	138.07	-6.047
92	50	Biased	141.91	142.27	0.364
93	50	Unbiased	145.4	141.6	-3.804
94	50	Unbiased	149.77	143.7	-6.077
95	50	Unbiased	137.49	135.65	-1.842
96	100	Biased	145.49	145.43	-0.06
97	100	Biased	145.73	143.79	-1.942
98	100	Biased	143.96	142.72	-1.241
99	100	Unbiased	139.41	139.94	0.538
100	100	Unbiased	136.52	137.37	0.852
101	100	Unbiased	142.67	138.78	-3.891
102	0	Correlation	139.16	133.78	-5.377
103	0	Correlation	146.4	136.77	-9.63

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	139.16	142.78	146.4	5.123	133.78	135.27	136.77	2.1157	-9.63	-7.5035	-5.377	3.0073
50	137.49	142.75	149.77	4.1519	135.65	140.92	144.97	3.2368	-6.077	-1.831	3.154	3.6522
100	136.52	142.29	145.73	3.6497	137.37	141.34	145.43	3.1267	-3.891	-0.95733	0.852	1.7873

Device Test: 19.12 RESET_SLEW_RATE_RISE(tsr_RESETB1_Rising/RESETB1/1.6/14/0/0/0/@RESET_SLEW_RATE_RISE





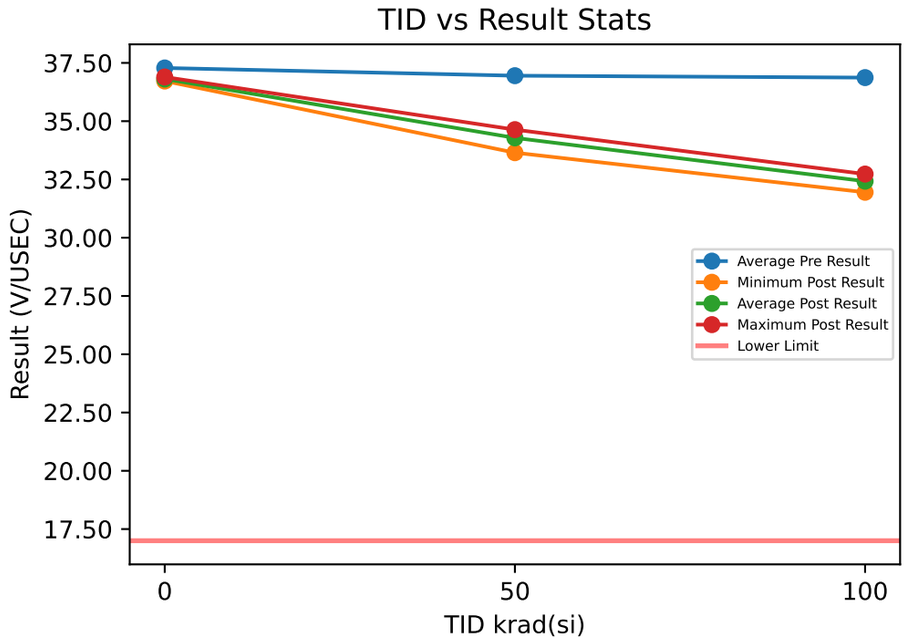
Test Results (Lower Limit = 17.0 (V/USEC))

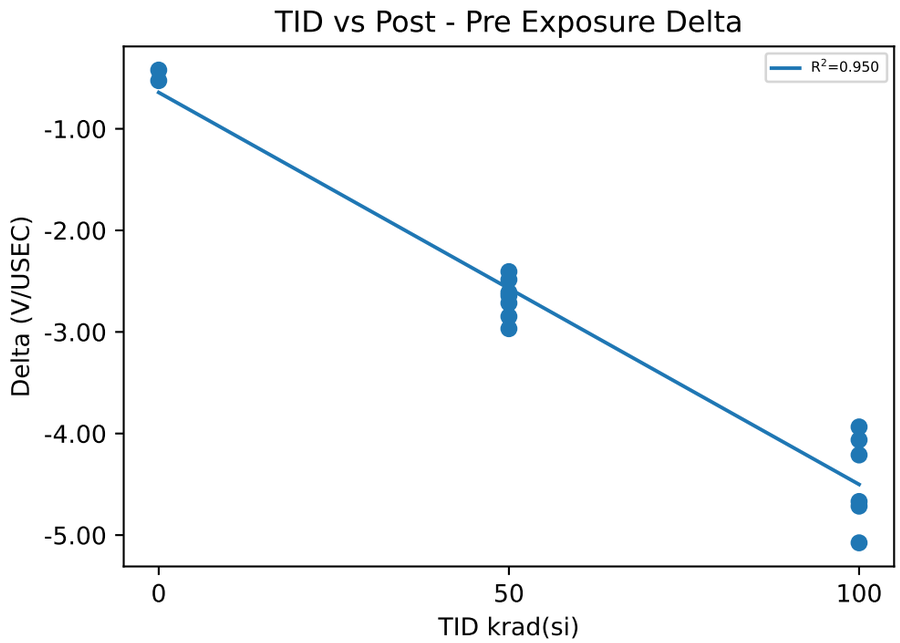
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	36.166	34.973	-1.193
89	50	Biased	36.334	34.759	-1.575
90	50	Biased	36.211	34.851	-1.36
92	50	Biased	35.808	34.297	-1.511
93	50	Unbiased	36.48	34.316	-2.164
94	50	Unbiased	36.607	34.249	-2.358
95	50	Unbiased	36.505	34.645	-1.86
96	100	Biased	36.315	33.754	-2.561
97	100	Biased	36.303	33.849	-2.454
98	100	Biased	36.081	33.809	-2.272
99	100	Unbiased	36.221	32.629	-3.592
100	100	Unbiased	36.436	32.727	-3.709
101	100	Unbiased	36.076	32.552	-3.524
102	0	Correlation	37.067	36.64	-0.427
103	0	Correlation	36.688	36.314	-0.374

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	36.688	36.877	37.067	0.26799	36.314	36.477	36.64	0.23052	-0.427	-0.4005	-0.374	0.037477
50	35.808	36.302	36.607	0.27011	34.249	34.584	34.973	0.29535	-2.358	-1.7173	-1.193	0.42735
100	36.076	36.239	36.436	0.1418	32.552	33.22	33.849	0.64285	-3.709	-3.0187	-2.272	0.6552

Device Test: 19.13 RESET_SLEW_RATE_RISE(tsr_RESETB2_Rising/RESETB2/1.6/14/0/0/0/@RESET_SLEW_RATE_RISE





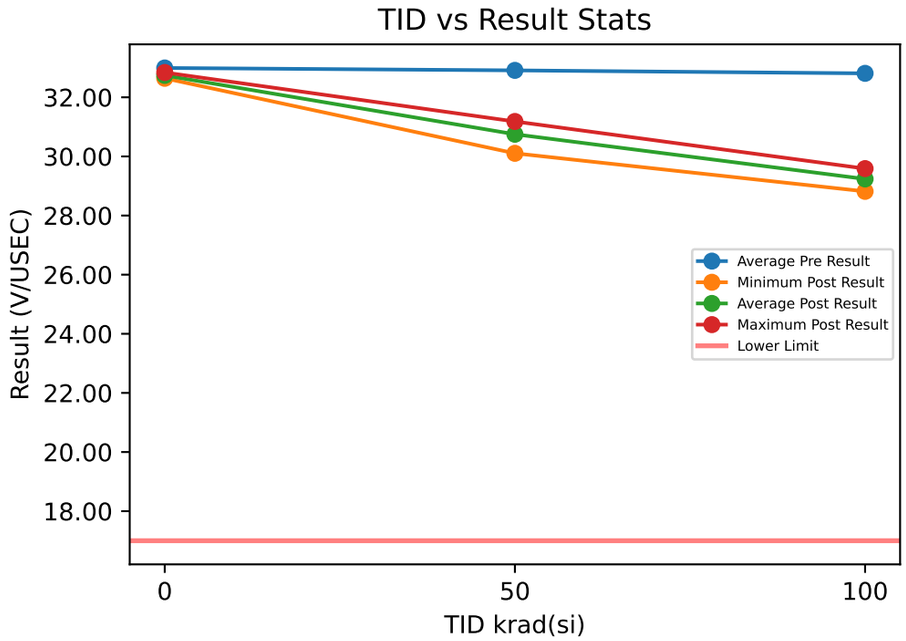
Test Results (Lower Limit = 17.0 (V/USEC))

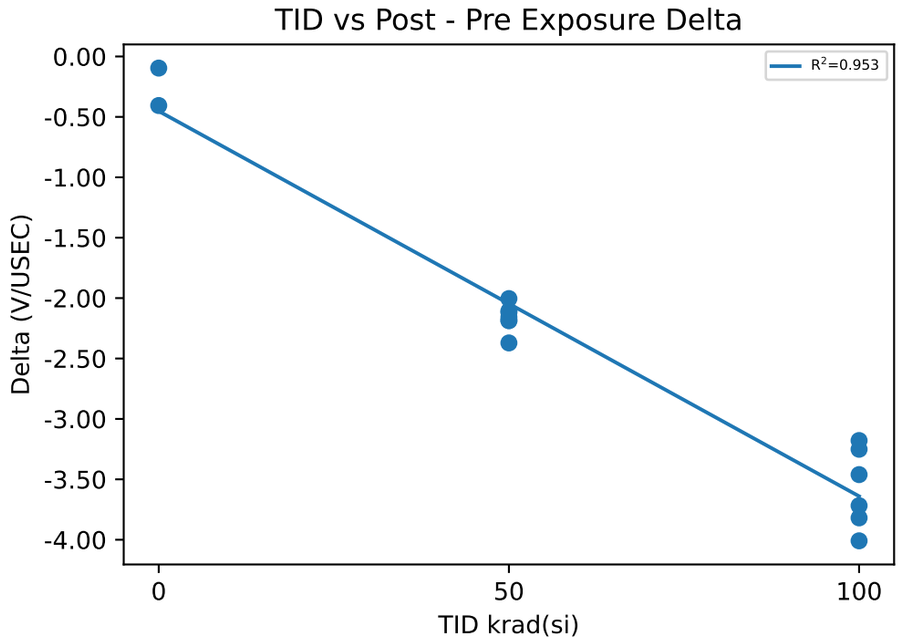
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	37.026	34.383	-2.643
89	50	Biased	37.21	34.242	-2.968
90	50	Biased	36.804	34.088	-2.716
92	50	Biased	36.496	33.648	-2.848
93	50	Unbiased	36.981	34.37	-2.611
94	50	Unbiased	37.099	34.614	-2.485
95	50	Unbiased	37.043	34.637	-2.406
96	100	Biased	37.018	32.349	-4.669
97	100	Biased	37.026	31.95	-5.076
98	100	Biased	36.808	32.093	-4.715
99	100	Unbiased	36.79	32.727	-4.063
100	100	Unbiased	36.666	32.731	-3.935
101	100	Unbiased	36.907	32.696	-4.211
102	0	Correlation	37.248	36.722	-0.526
103	0	Correlation	37.317	36.895	-0.422

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	37.248	37.282	37.317	0.04879	36.722	36.809	36.895	0.12233	-0.526	-0.474	-0.422	0.073539
50	36.496	36.951	37.21	0.23545	33.648	34.283	34.637	0.34044	-2.968	-2.6681	-2.406	0.19609
100	36.666	36.869	37.026	0.14104	31.95	32.424	32.731	0.34638	-5.076	-4.4448	-3.935	0.44317

Device Test: 19.14 RESET_SLEW_RATE_RISE(tsr_RESETB3_Rising/RESETB3/1.6/14/0/0/0/@RESET_SLEW_RATE_RISE





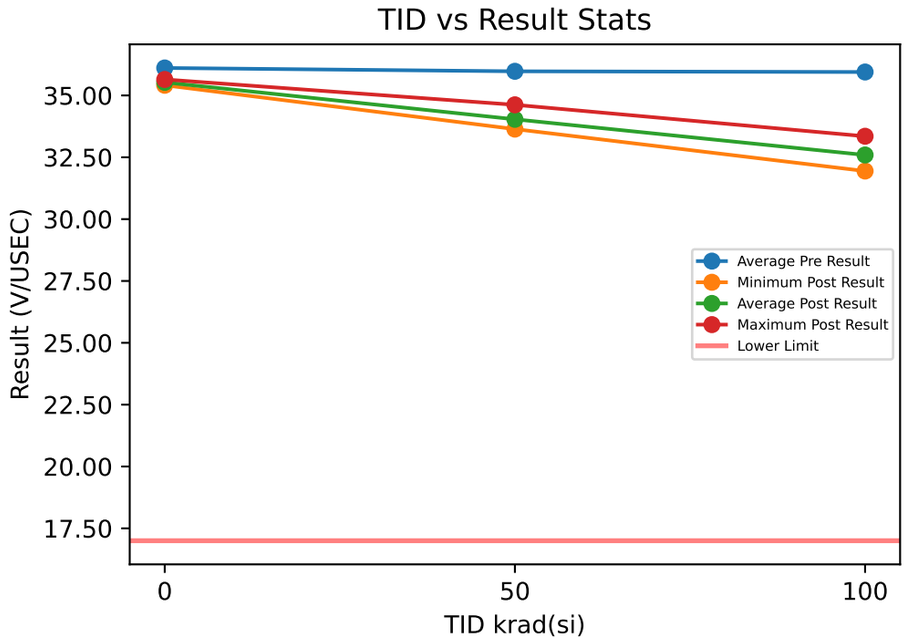
Test Results (Lower Limit = 17.0 (V/USEC))

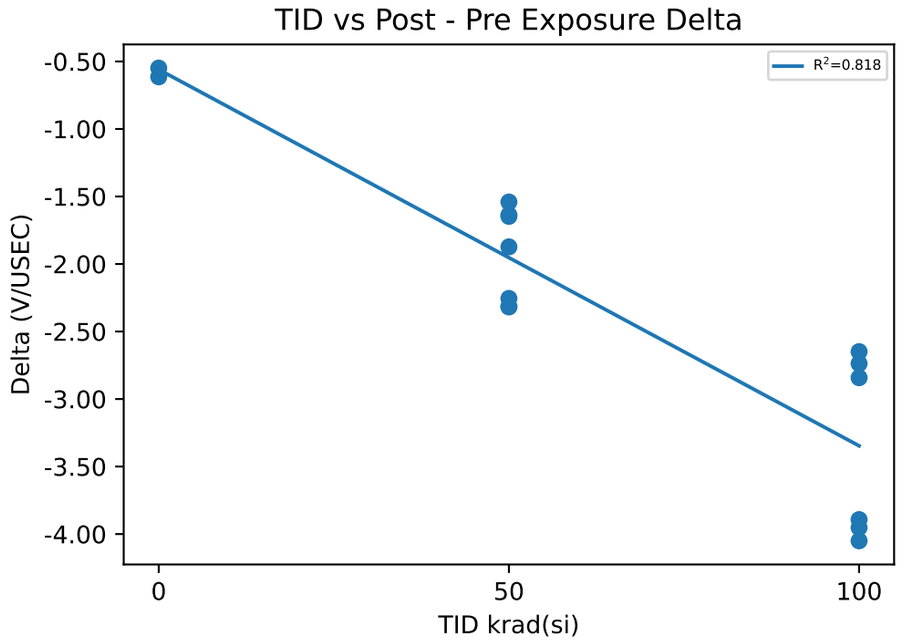
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	32.906	30.719	-2.187
89	50	Biased	33.185	31	-2.185
90	50	Biased	32.728	30.61	-2.118
92	50	Biased	32.476	30.105	-2.371
93	50	Unbiased	32.755	30.751	-2.004
94	50	Unbiased	33.288	31.182	-2.106
95	50	Unbiased	33.038	30.879	-2.159
96	100	Biased	32.919	29.201	-3.718
97	100	Biased	32.827	28.818	-4.009
98	100	Biased	32.925	29.106	-3.819
99	100	Unbiased	32.839	29.588	-3.251
100	100	Unbiased	32.638	29.459	-3.179
101	100	Unbiased	32.713	29.252	-3.461
102	0	Correlation	33.049	32.643	-0.406
103	0	Correlation	32.935	32.839	-0.096

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	32.935	32.992	33.049	0.08061	32.643	32.741	32.839	0.13859	-0.406	-0.251	-0.096	0.2192
50	32.476	32.911	33.288	0.28296	30.105	30.749	31.182	0.34214	-2.371	-2.1614	-2.004	0.11171
100	32.638	32.81	32.925	0.11422	28.818	29.237	29.588	0.27082	-4.009	-3.5728	-3.179	0.32958

Device Test: 19.15 RESET_SLEW_RATE_RISE(tsr_RESETB4_Rising/RESETB4/1.6/14/0/0/0/@RESET_SLEW_RATE_RISE





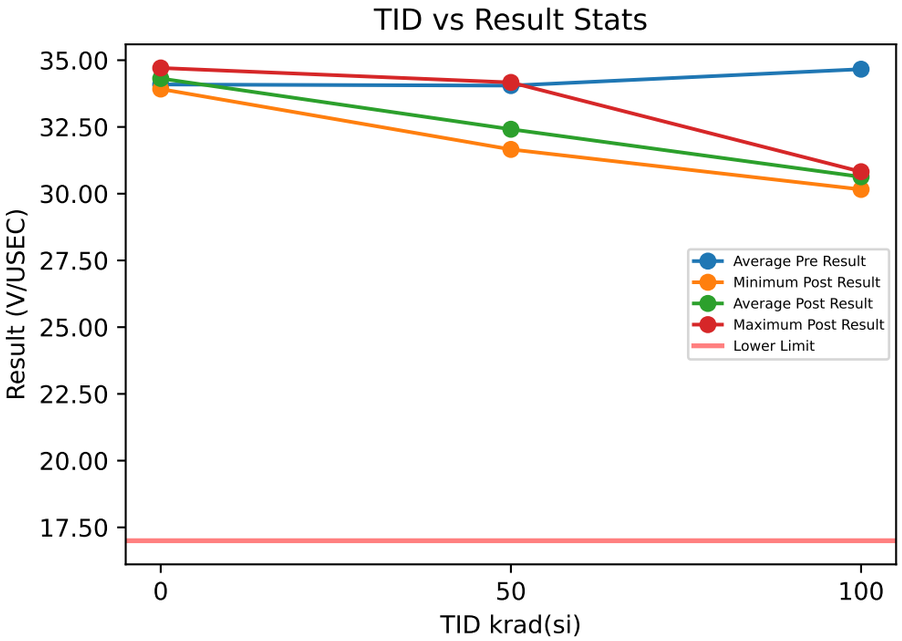
Test Results (Lower Limit = 17.0 (V/USEC))

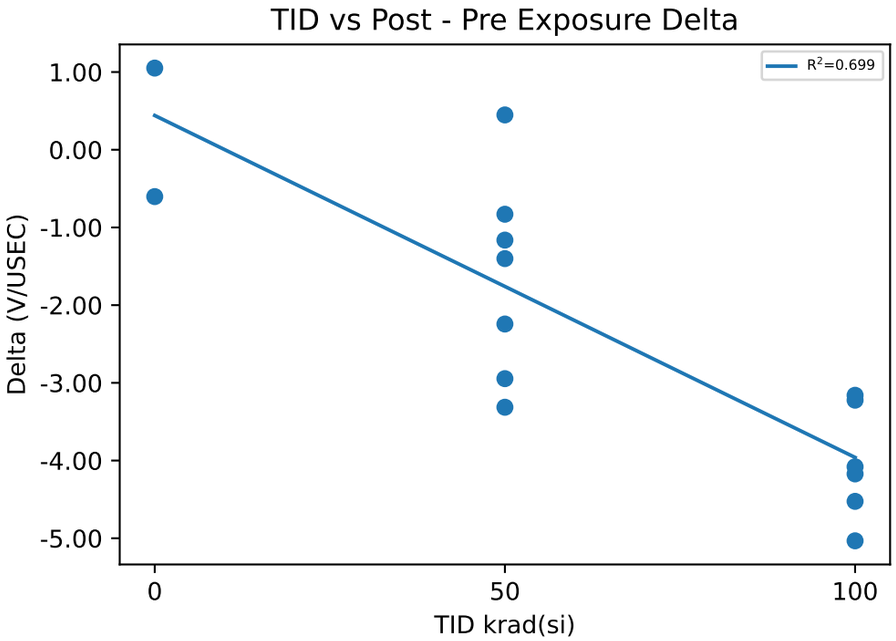
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	36.054	34.418	-1.636
89	50	Biased	36.268	34.621	-1.647
90	50	Biased	35.785	34.244	-1.541
92	50	Biased	35.622	33.749	-1.873
93	50	Unbiased	35.953	33.639	-2.314
94	50	Unbiased	36.157	33.902	-2.255
95	50	Unbiased	35.99	33.672	-2.318
96	100	Biased	36.192	33.35	-2.842
97	100	Biased	35.858	33.121	-2.737
98	100	Biased	35.744	33.095	-2.649
99	100	Unbiased	35.981	32.088	-3.893
100	100	Unbiased	35.896	31.944	-3.952
101	100	Unbiased	36.01	31.96	-4.05
102	0	Correlation	36.025	35.411	-0.614
103	0	Correlation	36.195	35.646	-0.549

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	36.025	36.11	36.195	0.12021	35.411	35.529	35.646	0.16617	-0.614	-0.5815	-0.549	0.045962
50	35.622	35.976	36.268	0.21857	33.639	34.035	34.621	0.39197	-2.318	-1.9406	-1.541	0.34736
100	35.744	35.947	36.192	0.15289	31.944	32.593	33.35	0.66042	-4.05	-3.3538	-2.649	0.67415

Device Test: 19.16 PWRGD_SLEW_RATE_RISE(tsr_PWRGD_Rising/PWRGD/1.6/14/0/0/0/@PWRGD_SLEW_RATE_RISE





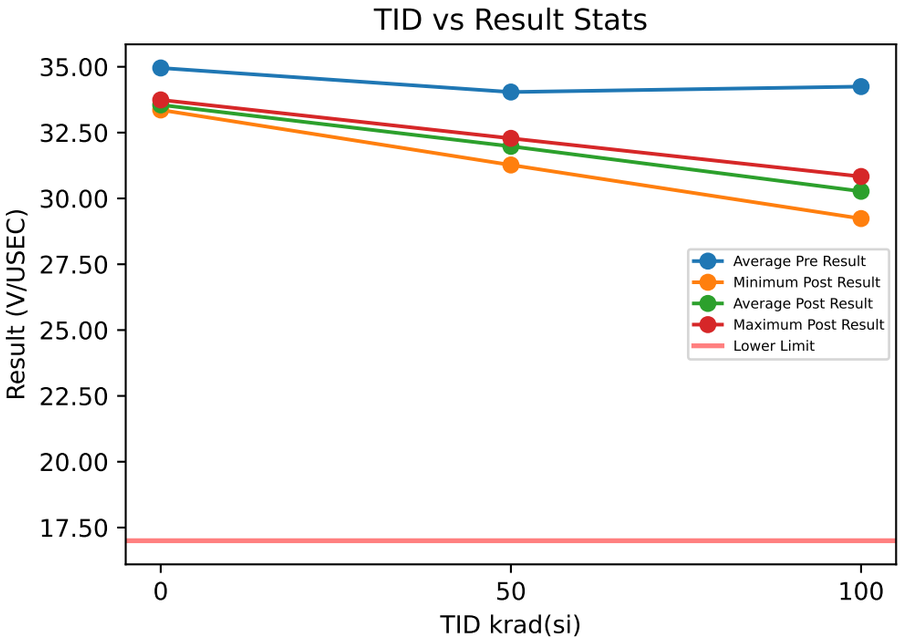
Test Results (Lower Limit = 17.0 (V/USEC))

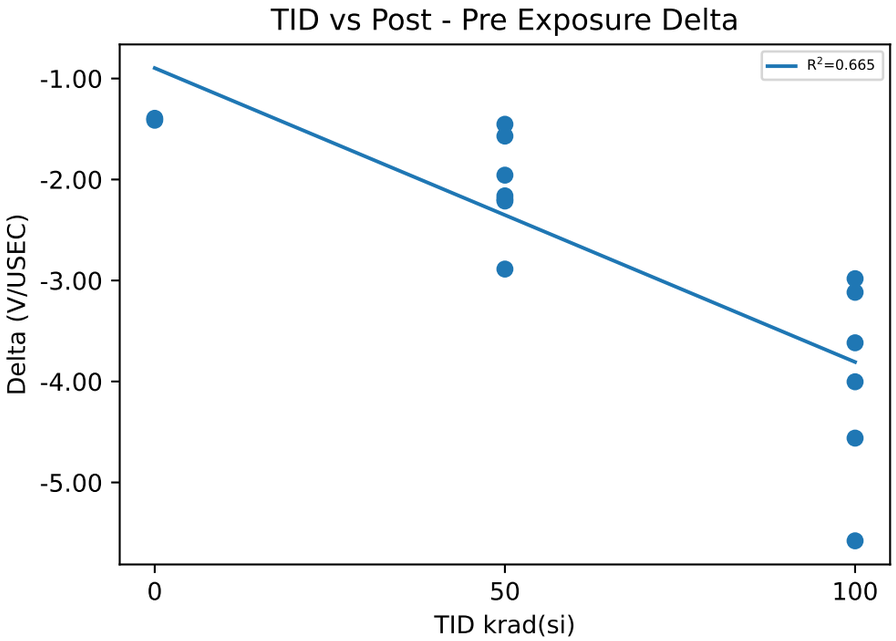
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	35.491	32.177	-3.314
89	50	Biased	33.767	32.366	-1.401
90	50	Biased	34.951	32.005	-2.946
92	50	Biased	33.901	31.658	-2.243
93	50	Unbiased	33.089	31.926	-1.163
94	50	Unbiased	33.719	34.167	0.448
95	50	Unbiased	33.425	32.595	-0.83
96	100	Biased	35.28	30.755	-4.525
97	100	Biased	34.656	30.576	-4.08
98	100	Biased	34.331	30.159	-4.172
99	100	Unbiased	33.987	30.764	-3.223
100	100	Unbiased	35.742	30.709	-5.033
101	100	Unbiased	33.983	30.823	-3.16
102	0	Correlation	34.523	33.92	-0.603
103	0	Correlation	33.658	34.709	1.051

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	33.658	34.091	34.523	0.61165	33.92	34.315	34.709	0.55791	-0.603	0.224	1.051	1.1696
50	33.089	34.049	35.491	0.85774	31.658	32.413	34.167	0.83078	-3.314	-1.6356	0.448	1.302
100	33.983	34.663	35.742	0.71758	30.159	30.631	30.823	0.24569	-5.033	-4.0322	-3.16	0.73237

Device Test: 19.17 WDO_SLEW_RATE_RISE(tsr_WDOB_Rising/WDOB/1.6/14/0/0/0/@WDO_SLEW_RATE_RISE)





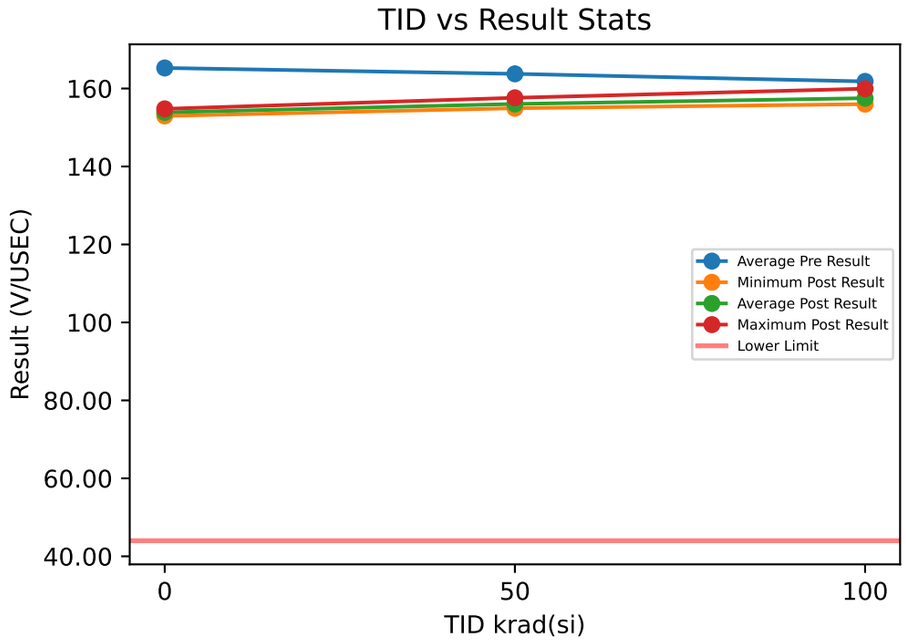
Test Results (Lower Limit = 17.0 (V/USEC))

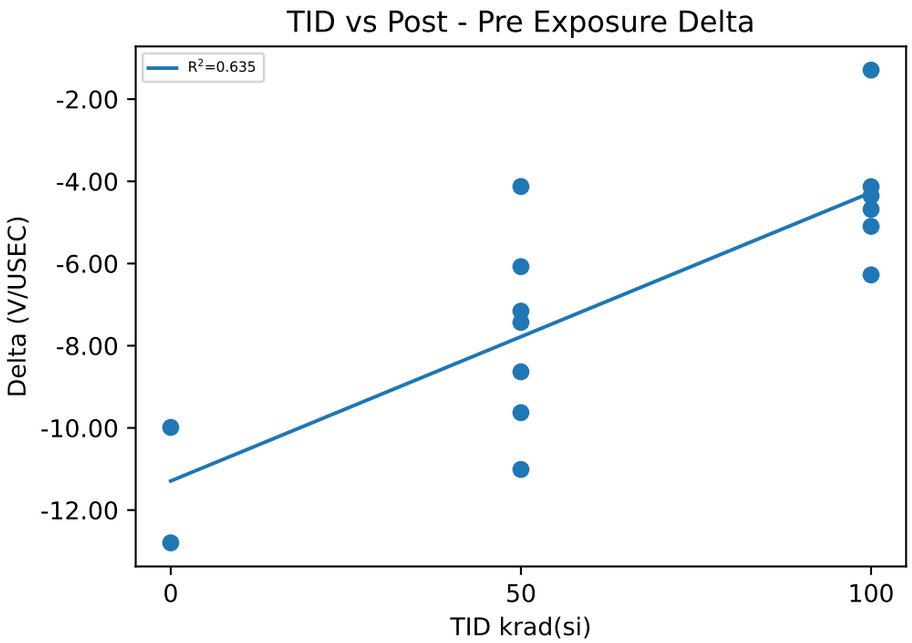
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	35.017	32.13	-2.887
89	50	Biased	33.735	32.282	-1.453
90	50	Biased	33.88	31.718	-2.162
92	50	Biased	33.227	31.27	-1.957
93	50	Unbiased	34.412	32.218	-2.194
94	50	Unbiased	34.403	32.19	-2.213
95	50	Unbiased	33.61	32.04	-1.57
96	100	Biased	34.233	30.23	-4.003
97	100	Biased	33.771	30.154	-3.617
98	100	Biased	34.813	29.235	-5.578
99	100	Unbiased	33.75	30.633	-3.117
100	100	Unbiased	33.523	30.541	-2.982
101	100	Unbiased	35.394	30.833	-4.561
102	0	Correlation	35.136	33.742	-1.394
103	0	Correlation	34.773	33.36	-1.413

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	34.773	34.955	35.136	0.25668	33.36	33.551	33.742	0.27011	-1.413	-1.4035	-1.394	0.013435
50	33.227	34.041	35.017	0.60404	31.27	31.978	32.282	0.36304	-2.887	-2.0623	-1.453	0.47519
100	33.523	34.247	35.394	0.7258	29.235	30.271	30.833	0.56718	-5.578	-3.9763	-2.982	0.97613

Device Test: 19.18 RESET_SLEW_RATE_FALL(tsr_RESETB1_Falling/RESETB1/1.6/14/0/0/0/@RESET_SLEW_RATE_FALL





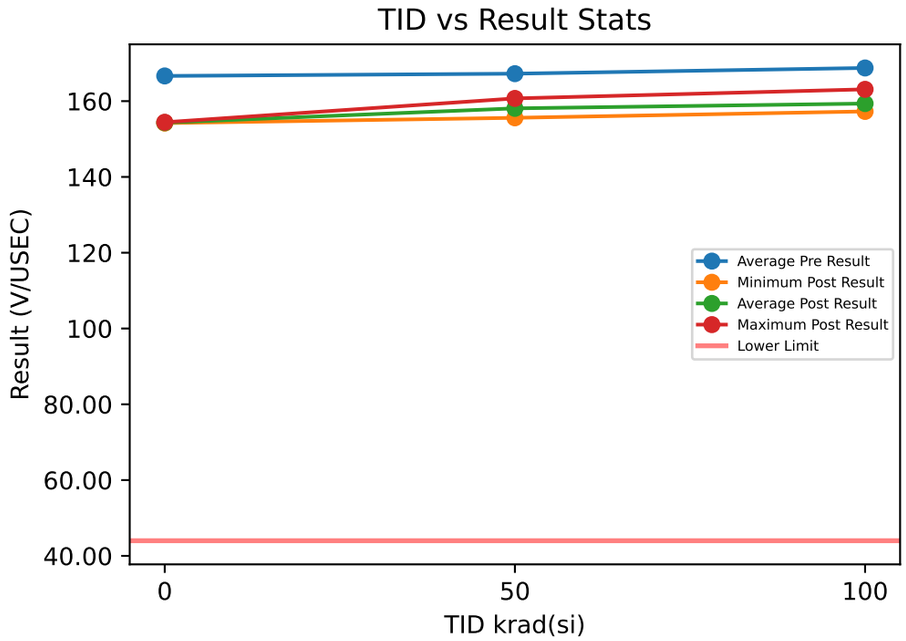
Test Results (Lower Limit = 44.0 (V/USEC))

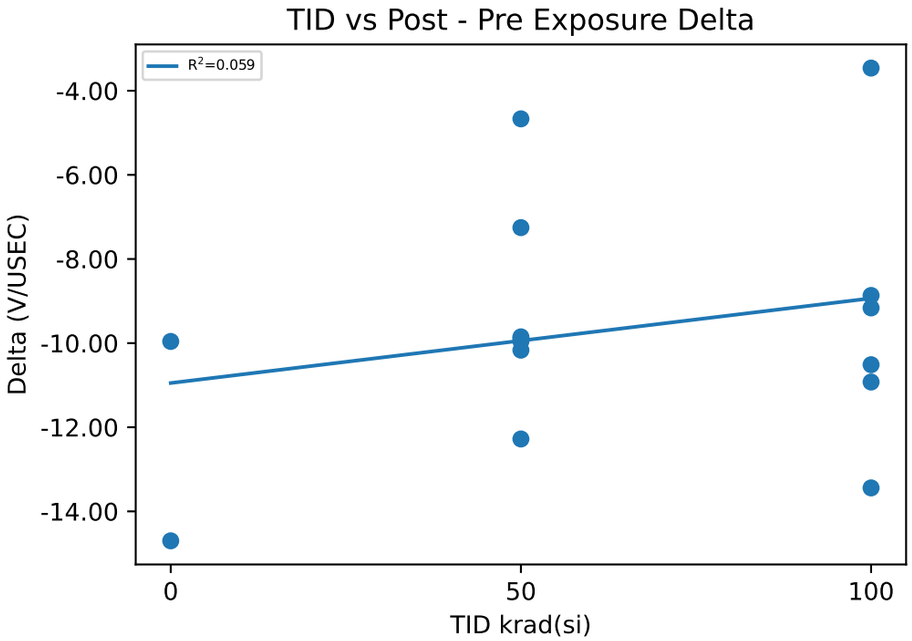
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	160.73	156.61	-4.126
89	50	Biased	167.24	157.61	-9.629
90	50	Biased	166	154.99	-11.012
92	50	Biased	164.95	156.31	-8.635
93	50	Unbiased	162.38	154.94	-7.433
94	50	Unbiased	163.24	156.08	-7.158
95	50	Unbiased	161.8	155.73	-6.076
96	100	Biased	162.16	157.06	-5.095
97	100	Biased	162.35	158.22	-4.13
98	100	Biased	164.3	159.95	-4.352
99	100	Unbiased	160.67	155.99	-4.682
100	100	Unbiased	158.93	157.63	-1.292
101	100	Unbiased	162.53	156.25	-6.277
102	0	Correlation	162.96	152.97	-9.988
103	0	Correlation	167.58	154.78	-12.797

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	162.96	165.27	167.58	3.2697	152.97	153.88	154.78	1.2834	-12.797	-11.392	-9.988	1.9863
50	160.73	163.76	167.24	2.3708	154.94	156.04	157.61	0.93844	-11.012	-7.7241	-4.126	2.2853
100	158.93	161.82	164.3	1.8299	155.99	157.52	159.95	1.454	-6.277	-4.3047	-1.292	1.6593

Device Test: 19.19 RESET_SLEW_RATE_FALL(tsr_RESETB2_Falling/RESETB2/1.6/14/0/0/0/@RESET_SLEW_RATE_FALL





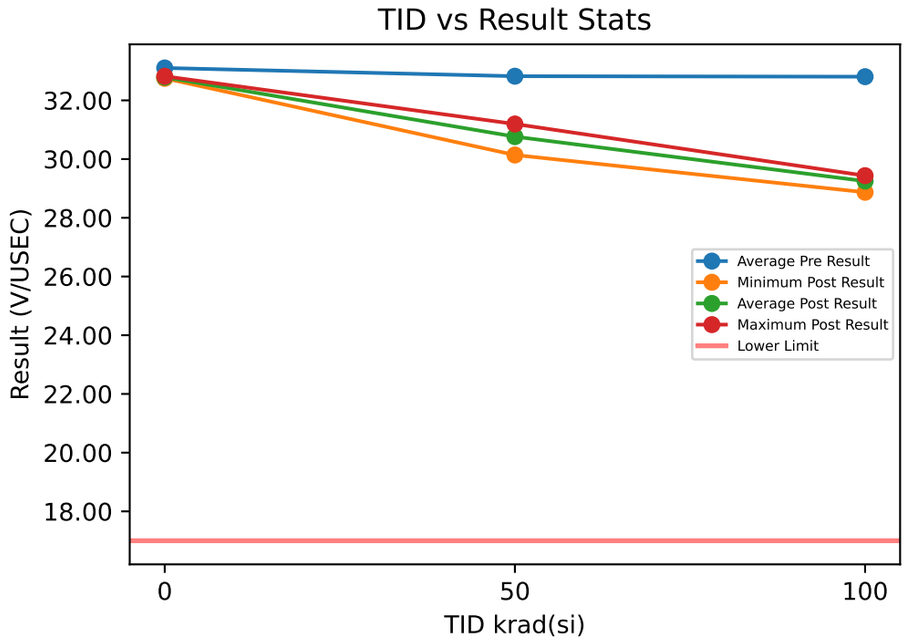
Test Results (Lower Limit = 44.0 (V/USEC))

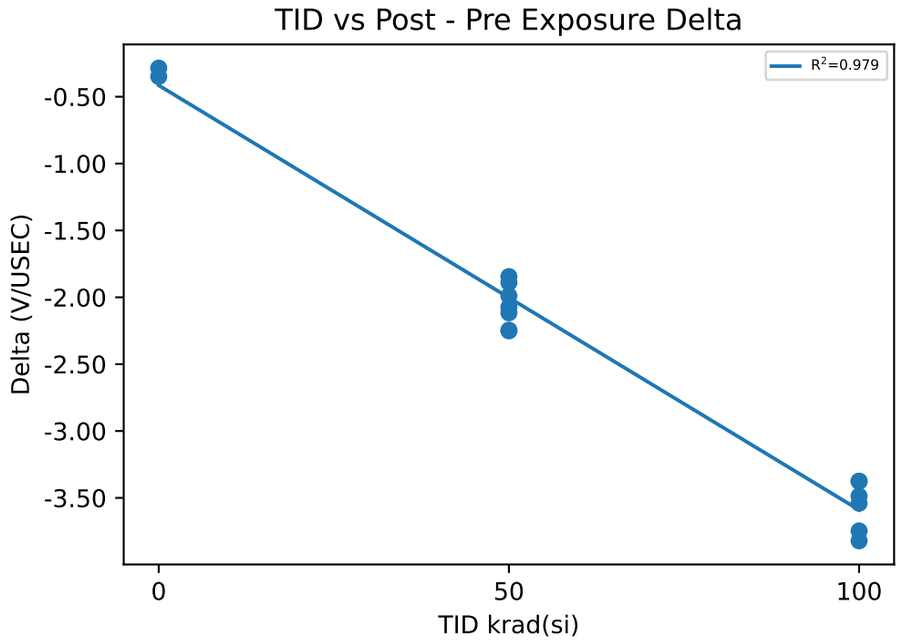
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	168.52	158.67	-9.851
89	50	Biased	173	160.72	-12.279
90	50	Biased	167.13	159.88	-7.254
92	50	Biased	163.96	159.29	-4.668
93	50	Unbiased	165.56	155.6	-9.959
94	50	Unbiased	167.03	156.86	-10.167
95	50	Unbiased	165.53	155.65	-9.889
96	100	Biased	170.18	161.01	-9.163
97	100	Biased	167.48	158.62	-8.867
98	100	Biased	166.57	163.11	-3.461
99	100	Unbiased	168.72	158.21	-10.513
100	100	Unbiased	168.82	157.9	-10.925
101	100	Unbiased	170.73	157.29	-13.442
102	0	Correlation	169.13	154.43	-14.7
103	0	Correlation	164.17	154.21	-9.96

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	164.17	166.65	169.13	3.508	154.21	154.32	154.43	0.15627	-14.7	-12.33	-9.96	3.3517
50	163.96	167.25	173	2.9252	155.6	158.09	160.72	2.0646	-12.279	-9.1524	-4.668	2.4563
100	166.57	168.75	170.73	1.5678	157.29	159.36	163.11	2.2424	-13.442	-9.3952	-3.461	3.3321

Device Test: 19.2 RESET_SLEW_RATE_RISE(tsr_RESETB3_Rising/RESETB3/1.6/3/0/0/0/@RESET_SLEW_RATE_RISE)





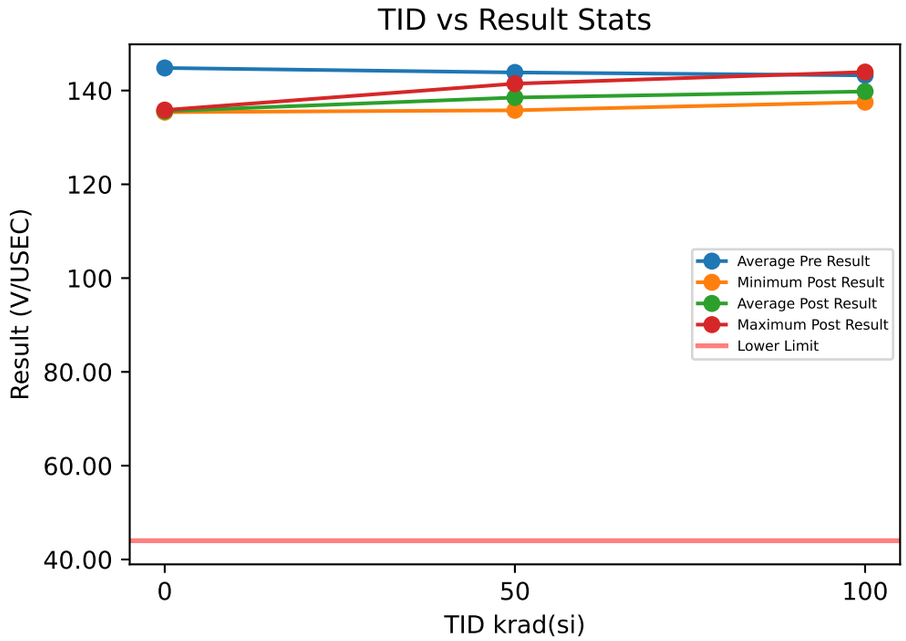
Test Results (Lower Limit = 17.0 (V/USEC))

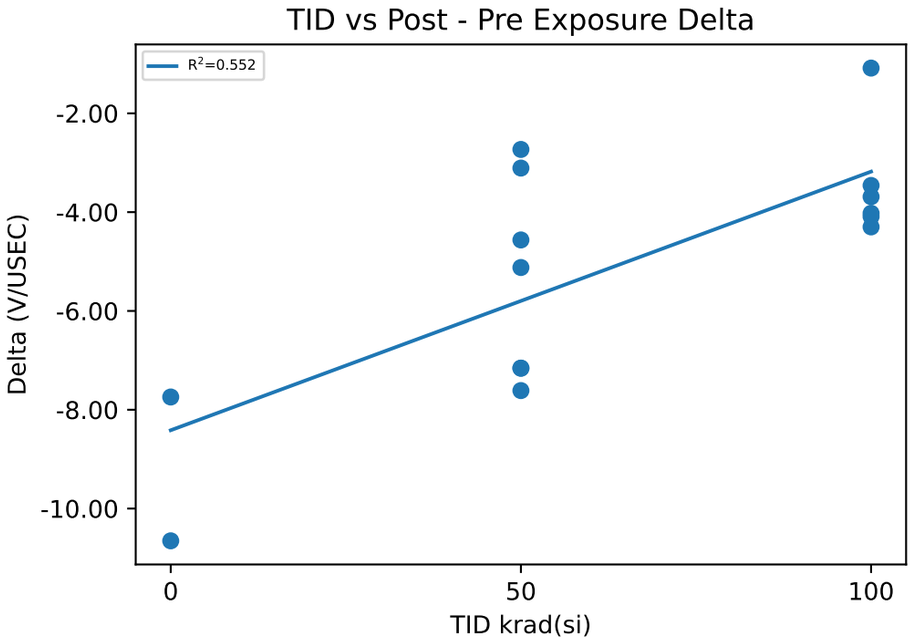
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	32.702	30.713	-1.989
89	50	Biased	33.188	30.942	-2.246
90	50	Biased	32.708	30.592	-2.116
92	50	Biased	32.39	30.139	-2.251
93	50	Unbiased	32.695	30.85	-1.845
94	50	Unbiased	33.085	31.195	-1.89
95	50	Unbiased	32.992	30.919	-2.073
96	100	Biased	32.965	29.218	-3.747
97	100	Biased	32.691	28.87	-3.821
98	100	Biased	32.709	29.169	-3.54
99	100	Unbiased	32.921	29.435	-3.486
100	100	Unbiased	32.769	29.393	-3.376
101	100	Unbiased	32.787	29.412	-3.375
102	0	Correlation	33.037	32.751	-0.286
103	0	Correlation	33.17	32.821	-0.349

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	33.037	33.103	33.17	0.094045	32.751	32.786	32.821	0.049497	-0.349	-0.3175	-0.286	0.044548
50	32.39	32.823	33.188	0.27754	30.139	30.764	31.195	0.33458	-2.251	-2.0586	-1.845	0.16049
100	32.691	32.807	32.965	0.11213	28.87	29.25	29.435	0.21582	-3.821	-3.5575	-3.375	0.18815

Device Test: 19.20 RESET_SLEW_RATE_FALL(tsr_RESETB3_Falling/RESETB3/1.6/14/0/0/0/@RESET_SLEW_RATE_FALL





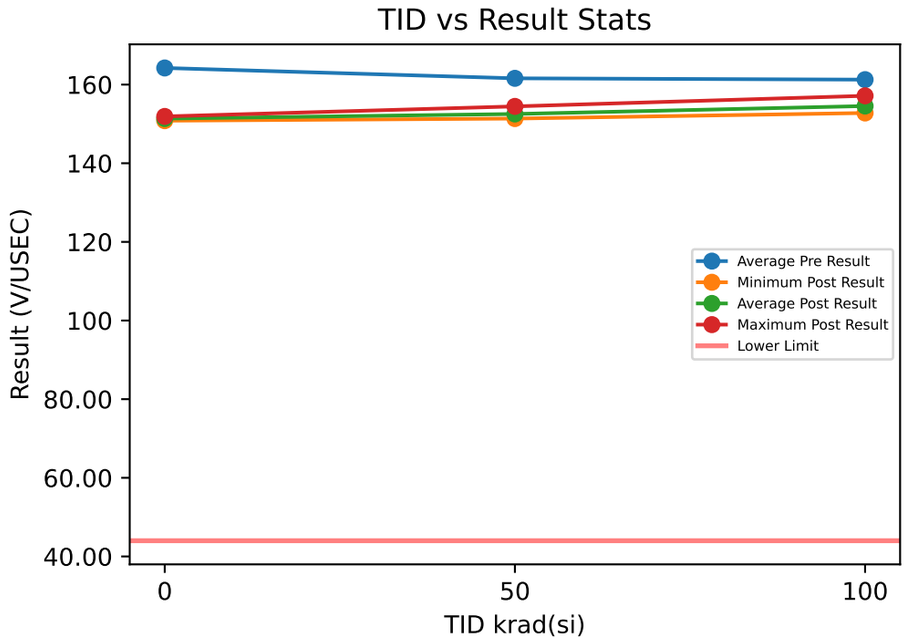
Test Results (Lower Limit = 44.0 (V/USEC))

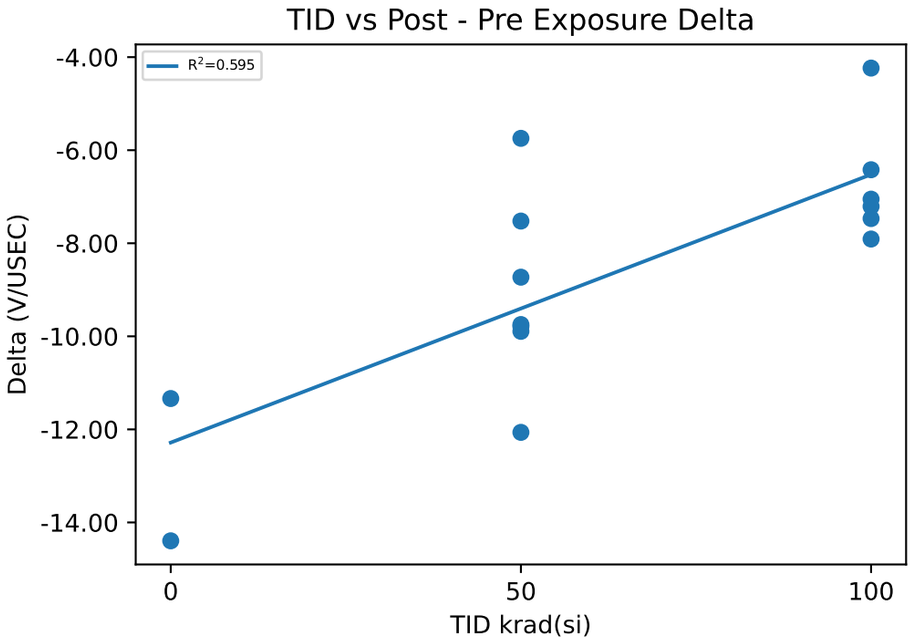
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	141.64	138.91	-2.731
89	50	Biased	144.57	141.46	-3.108
90	50	Biased	144.63	140.07	-4.563
92	50	Biased	145.01	139.89	-5.121
93	50	Unbiased	142.94	135.78	-7.158
94	50	Unbiased	144.66	137.51	-7.158
95	50	Unbiased	143.5	135.89	-7.612
96	100	Biased	144.87	141.19	-3.688
97	100	Biased	140.79	139.71	-1.084
98	100	Biased	148.02	143.94	-4.089
99	100	Unbiased	142.75	138.45	-4.299
100	100	Unbiased	142	137.97	-4.023
101	100	Unbiased	140.98	137.52	-3.46
102	0	Correlation	143.13	135.39	-7.742
103	0	Correlation	146.49	135.84	-10.653

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	143.13	144.81	146.49	2.3766	135.39	135.61	135.84	0.3182	-10.653	-9.1975	-7.742	2.0584
50	141.64	143.85	145.01	1.2223	135.78	138.5	141.46	2.181	-7.612	-5.3501	-2.731	2.0088
100	140.79	143.24	148.02	2.7729	137.52	139.8	143.94	2.4244	-4.299	-3.4405	-1.084	1.1926

Device Test: 19.21 RESET_SLEW_RATE_FALL(tsr_RESETB4_Falling/RESETB4/1.6/14/0/0/0/@RESET_SLEW_RATE_FALL





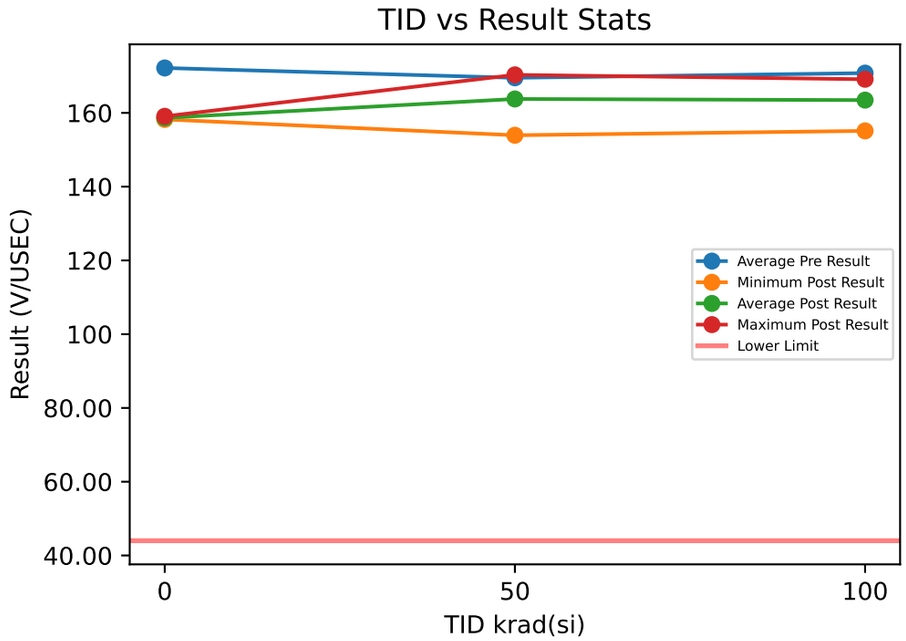
Test Results (Lower Limit = 44.0 (V/USEC))

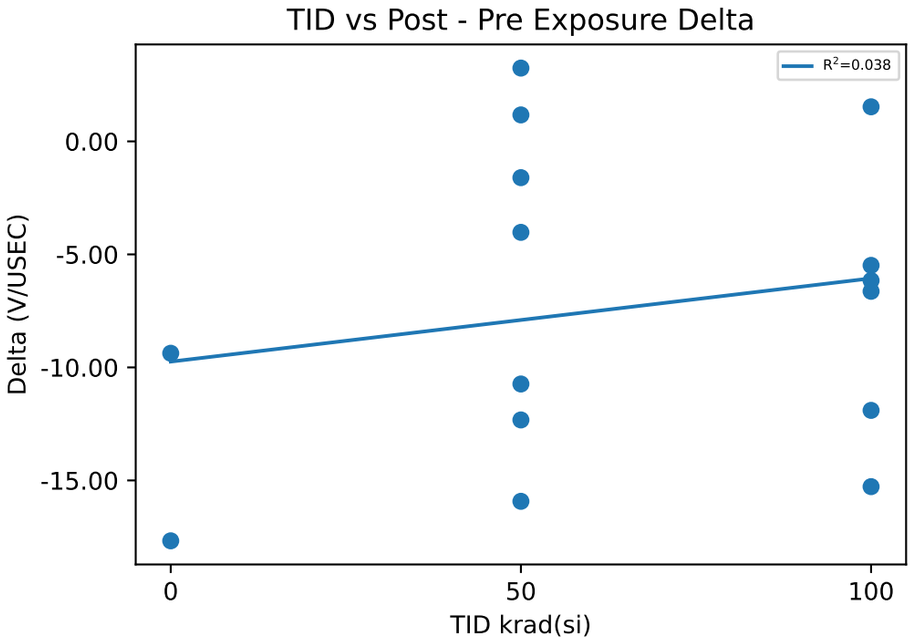
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	161.44	151.66	-9.789
89	50	Biased	164.2	154.46	-9.747
90	50	Biased	158.57	152.83	-5.745
92	50	Biased	162.17	152.28	-9.893
93	50	Unbiased	163.42	151.36	-12.064
94	50	Unbiased	161.24	153.72	-7.523
95	50	Unbiased	160.12	151.4	-8.729
96	100	Biased	162.9	155.43	-7.469
97	100	Biased	161.15	153.94	-7.208
98	100	Biased	163.57	157.15	-6.42
99	100	Unbiased	157.01	152.78	-4.235
100	100	Unbiased	161.32	154.27	-7.052
101	100	Unbiased	161.64	153.73	-7.909
102	0	Correlation	163.24	151.91	-11.337
103	0	Correlation	165.22	150.82	-14.395

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	163.24	164.23	165.22	1.3965	150.82	151.36	151.91	0.7658	-14.395	-12.866	-11.337	2.1623
50	158.57	161.6	164.2	1.9114	151.36	152.53	154.46	1.2044	-12.064	-9.07	-5.745	2.0076
100	157.01	161.26	163.57	2.2888	152.78	154.55	157.15	1.5352	-7.909	-6.7155	-4.235	1.3106

Device Test: 19.22 PWRGD_SLEW_RATE_FALL(tsr_PWRGD_Falling/PWRGD/1.6/14/0/0/0/@PWRGD_SLEW_RATE_FALL





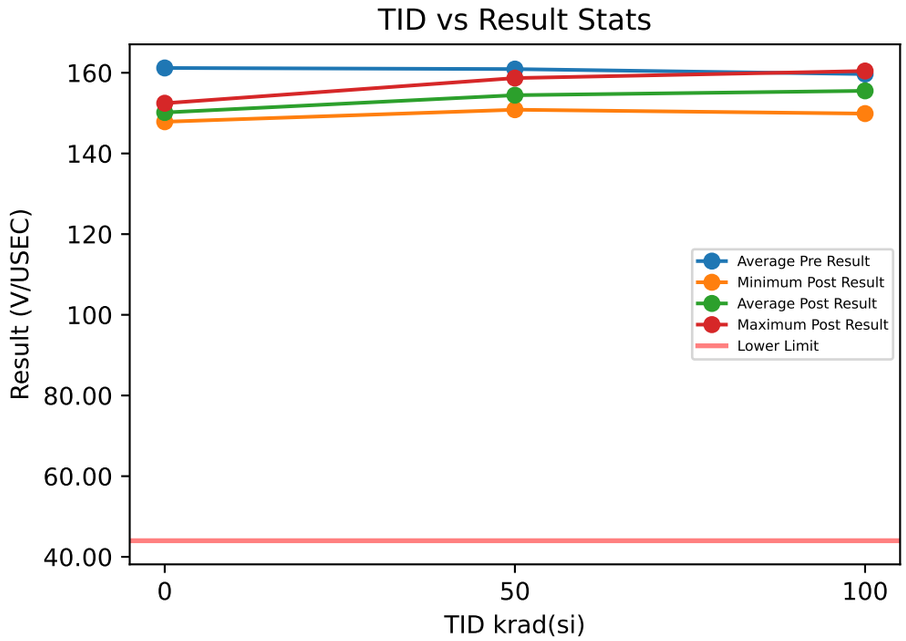
Test Results (Lower Limit = 44.0 (V/USEC))

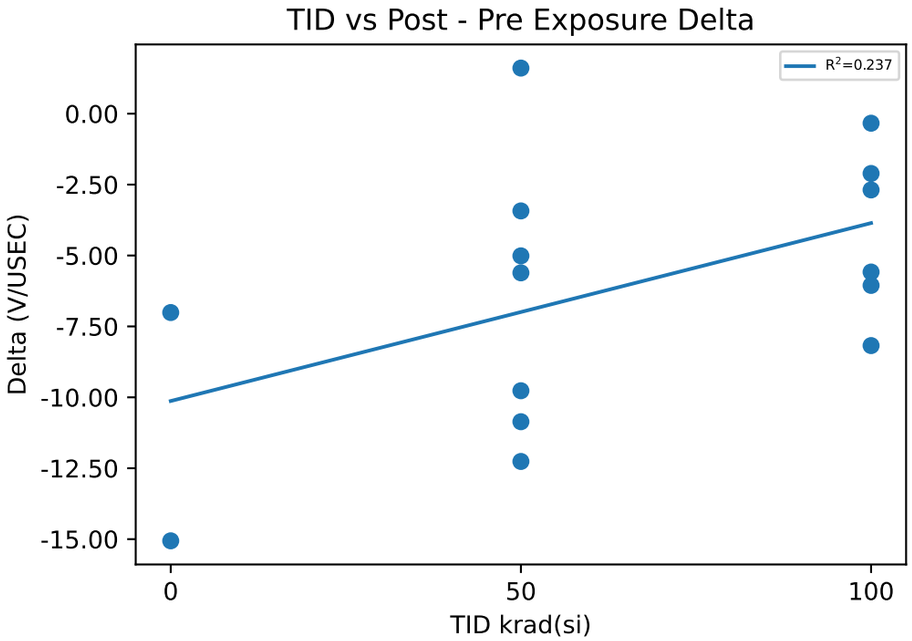
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	175.31	164.58	-10.734
89	50	Biased	167.07	170.31	3.243
90	50	Biased	165.44	161.42	-4.025
92	50	Biased	167.46	168.63	1.171
93	50	Unbiased	176.72	160.8	-15.924
94	50	Unbiased	168.35	166.74	-1.605
95	50	Unbiased	166.26	153.94	-12.324
96	100	Biased	174.61	169.12	-5.486
97	100	Biased	165.99	167.52	1.53
98	100	Biased	173.89	167.73	-6.157
99	100	Unbiased	161.75	155.12	-6.633
100	100	Unbiased	173.19	157.92	-15.275
101	100	Unbiased	175.28	163.38	-11.901
102	0	Correlation	168.45	159.07	-9.374
103	0	Correlation	175.91	158.24	-17.672

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	168.45	172.18	175.91	5.2764	158.24	158.66	159.07	0.59114	-17.672	-13.523	-9.374	5.8676
50	165.44	169.52	176.72	4.5511	153.94	163.77	170.31	5.5809	-15.924	-5.7426	3.243	7.3087
100	161.75	170.78	175.28	5.565	155.12	163.46	169.12	5.781	-15.275	-7.3203	1.53	5.7927

Device Test: 19.23 WDO_SLEW_RATE_FALL(tsr_WDOB_Falling/WDOB/1.6/14/0/0/0/@WDO_SLEW_RATE_FALL)





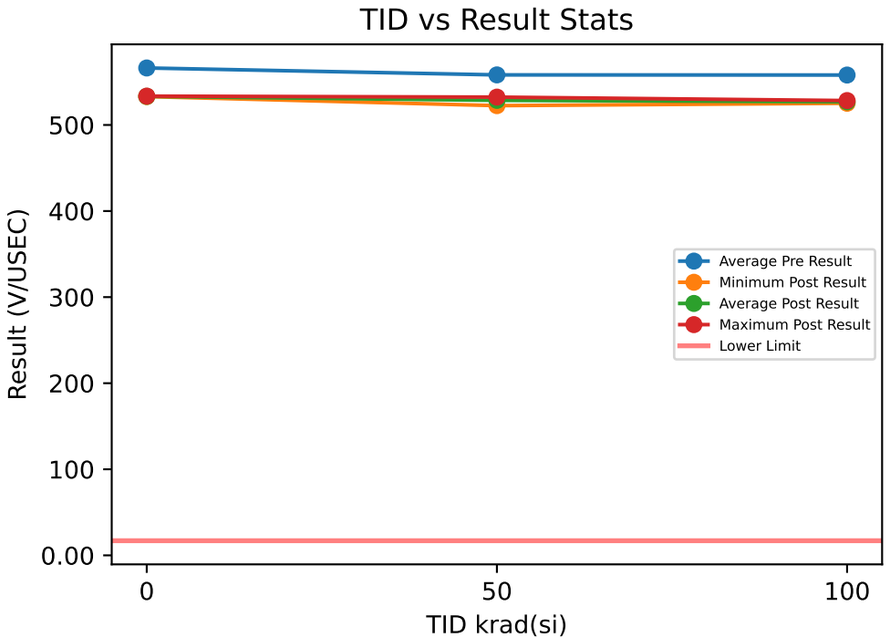
Test Results (Lower Limit = 44.0 (V/USEC))

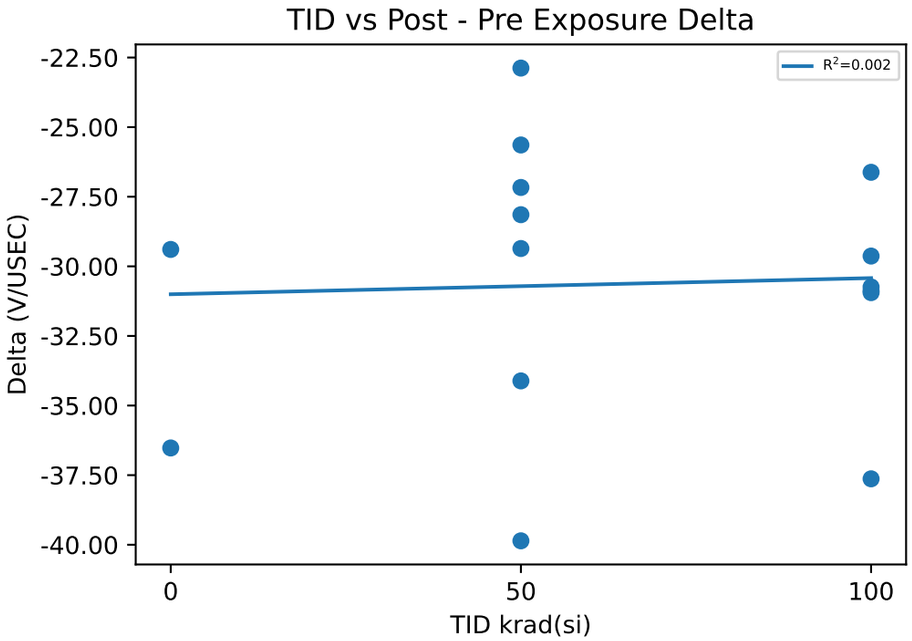
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	154.66	156.27	1.608
89	50	Biased	166.07	156.3	-9.768
90	50	Biased	160.58	154.97	-5.611
92	50	Biased	155.63	152.2	-3.428
93	50	Unbiased	163.1	150.84	-12.261
94	50	Unbiased	169.54	158.68	-10.86
95	50	Unbiased	156.83	151.82	-5.012
96	100	Biased	160.28	158.17	-2.108
97	100	Biased	160.17	157.48	-2.688
98	100	Biased	160.77	160.44	-0.336
99	100	Unbiased	155.94	149.88	-6.054
100	100	Unbiased	161.94	153.76	-8.176
101	100	Unbiased	158.98	153.4	-5.583
102	0	Correlation	162.92	147.86	-15.059
103	0	Correlation	159.46	152.45	-7.011

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	159.46	161.19	162.92	2.4438	147.86	150.16	152.45	3.247	-15.059	-11.035	-7.011	5.6908
50	154.66	160.92	169.54	5.6219	150.84	154.44	158.68	2.8844	-12.261	-6.476	1.608	4.8486
100	155.94	159.68	161.94	2.0692	149.88	155.52	160.44	3.8578	-8.176	-4.1575	-0.336	2.9237

Device Test: 19.24 RESET_SLEW_RATE_RISE(tsr_RESETB1_Rising/RESETB1/7/3/0/0/0/@RESET_SLEW_RATE_RISE)





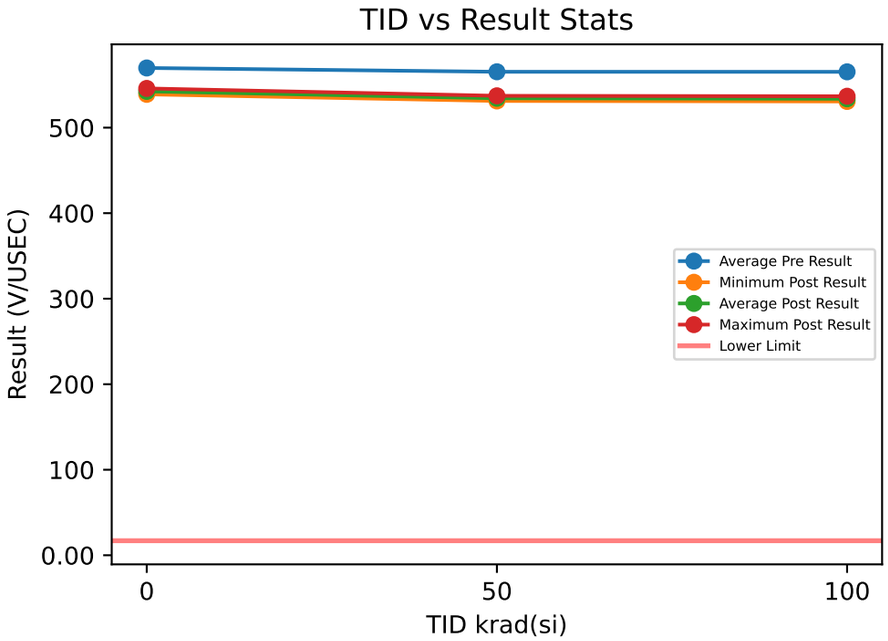
Test Results (Lower Limit = 17.0 (V/USEC))

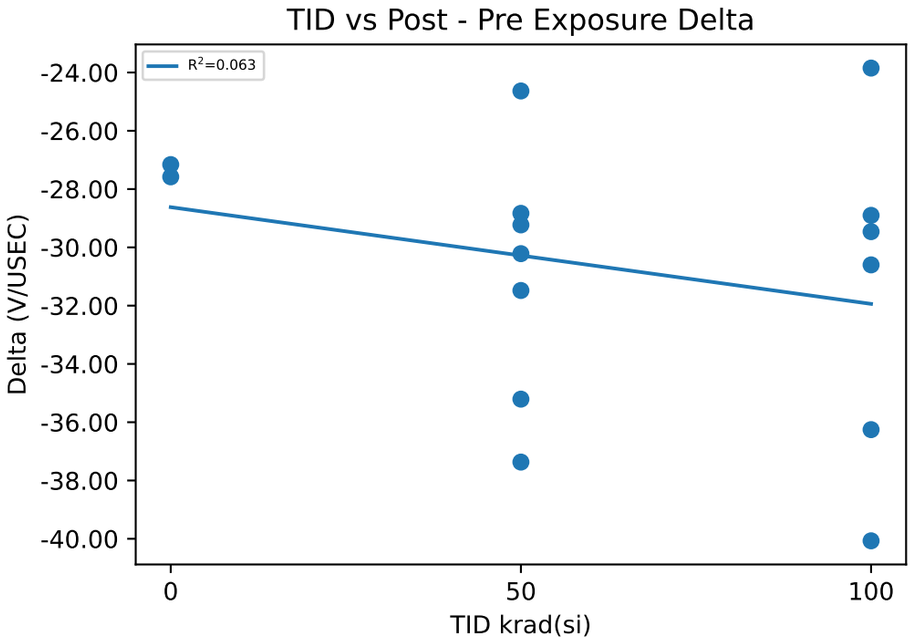
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	553.85	530.97	-22.879
89	50	Biased	558.77	530.62	-28.145
90	50	Biased	556.6	527.24	-29.36
92	50	Biased	548.09	522.45	-25.641
93	50	Unbiased	558.44	531.28	-27.167
94	50	Unbiased	564.97	525.11	-39.859
95	50	Unbiased	566.46	532.35	-34.115
96	100	Biased	555.95	526.32	-29.631
97	100	Biased	558.07	527.33	-30.74
98	100	Biased	564.6	526.97	-37.632
99	100	Unbiased	559.21	528.34	-30.874
100	100	Unbiased	551.85	525.22	-26.622
101	100	Unbiased	558.35	527.4	-30.945
102	0	Correlation	562.89	533.5	-29.393
103	0	Correlation	569.52	532.99	-36.524

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	562.89	566.21	569.52	4.6832	532.99	533.25	533.5	0.35921	-36.524	-32.959	-29.393	5.0424
50	548.09	558.17	566.46	6.2997	522.45	528.57	532.35	3.7134	-39.859	-29.595	-22.879	5.6946
100	551.85	558	564.6	4.1772	525.22	526.93	528.34	1.0643	-37.632	-31.074	-26.622	3.6077

Device Test: 19.25 RESET_SLEW_RATE_RISE(tsr_RESETB2_Rising/RESETB2/7/3/0/0/0/@RESET_SLEW_RATE_RISE)





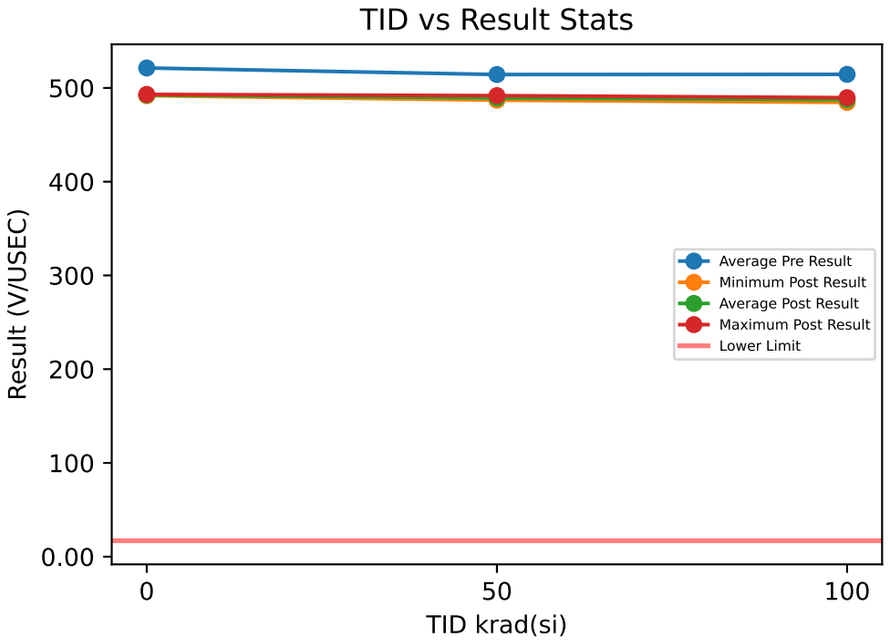
Test Results (Lower Limit = 17.0 (V/USEC))

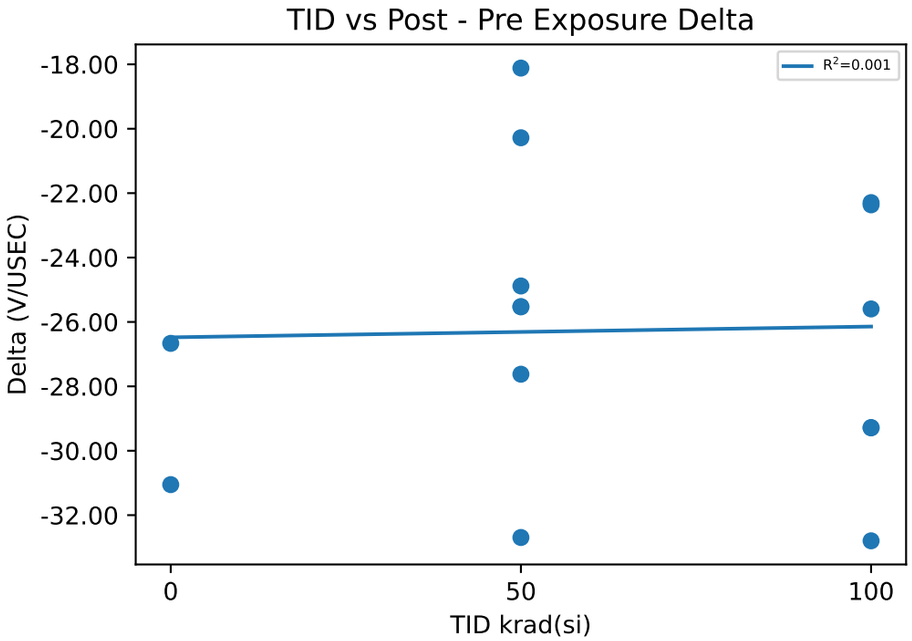
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	572.43	537.23	-35.208
89	50	Biased	559.83	535.19	-24.634
90	50	Biased	569.61	532.24	-37.368
92	50	Biased	560.43	531.2	-29.229
93	50	Unbiased	567.65	536.17	-31.48
94	50	Unbiased	565.33	535.11	-30.216
95	50	Unbiased	561.97	533.13	-28.833
96	100	Biased	561.51	532.61	-28.902
97	100	Biased	563.27	532.66	-30.601
98	100	Biased	563.05	533.59	-29.461
99	100	Unbiased	560.08	536.23	-23.848
100	100	Unbiased	570.69	530.62	-40.07
101	100	Unbiased	572.98	536.72	-36.255
102	0	Correlation	566.1	538.94	-27.16
103	0	Correlation	573.44	545.86	-27.58

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	566.1	569.77	573.44	5.1887	538.94	542.4	545.86	4.8918	-27.58	-27.37	-27.16	0.29698
50	559.83	565.32	572.43	4.8267	531.2	534.33	537.23	2.1885	-37.368	-30.995	-24.634	4.2321
100	560.08	565.26	572.98	5.2688	530.62	533.74	536.72	2.337	-40.07	-31.523	-23.848	5.7675

Device Test: 19.26 RESET_SLEW_RATE_RISE(tsr_RESETB3_Rising/RESETB3/7/3/0/0/0/@RESET_SLEW_RATE_RISE)





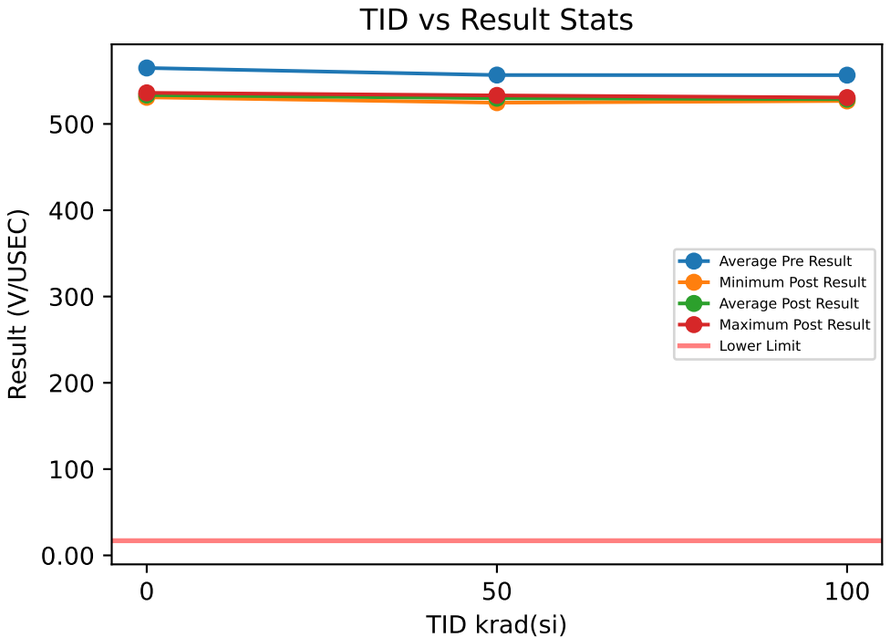
Test Results (Lower Limit = 17.0 (V/USEC))

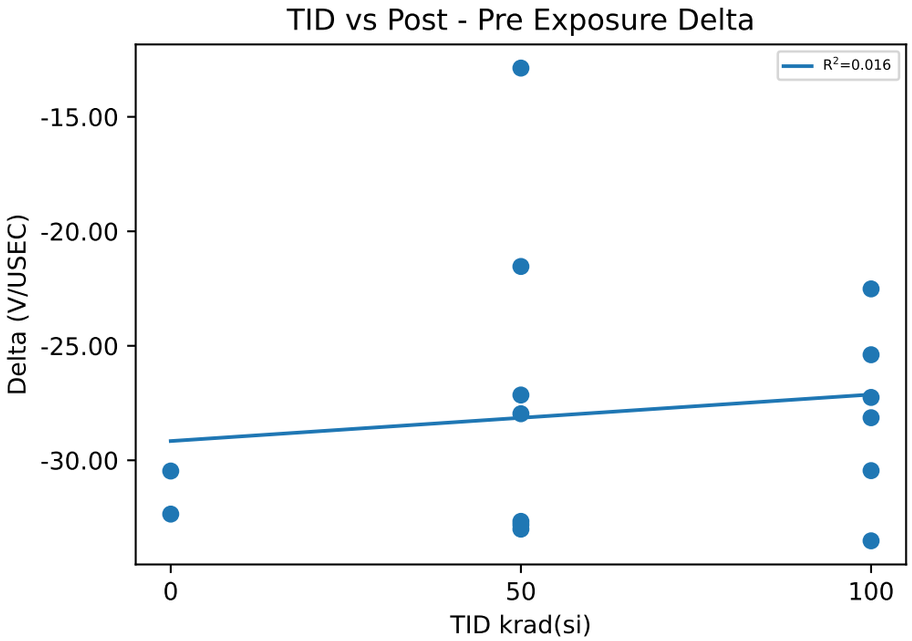
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	509.9	491.78	-18.116
89	50	Biased	516.72	491.2	-25.526
90	50	Biased	514.56	486.94	-27.623
92	50	Biased	508.56	488.28	-20.28
93	50	Unbiased	520.83	488.13	-32.694
94	50	Unbiased	515.31	490.43	-24.883
95	50	Unbiased	514.31	488.78	-25.529
96	100	Biased	519.13	486.34	-32.797
97	100	Biased	510.19	484.59	-25.596
98	100	Biased	518.9	489.62	-29.279
99	100	Unbiased	517.89	488.61	-29.289
100	100	Unbiased	509.44	487.08	-22.363
101	100	Unbiased	511.26	488.97	-22.294
102	0	Correlation	518.44	491.77	-26.665
103	0	Correlation	524.15	493.09	-31.052

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	518.44	521.29	524.15	4.0369	491.77	492.43	493.09	0.9348	-31.052	-28.858	-26.665	3.1021
50	508.56	514.31	520.83	4.1202	486.94	489.36	491.78	1.7914	-32.694	-24.95	-18.116	4.7662
100	509.44	514.47	519.13	4.626	484.59	487.53	489.62	1.8905	-32.797	-26.936	-22.294	4.234

Device Test: 19.27 RESET_SLEW_RATE_RISE(tsr_RESETB4_Rising/RESETB4/7/3/0/0/0/@RESET_SLEW_RATE_RISE)





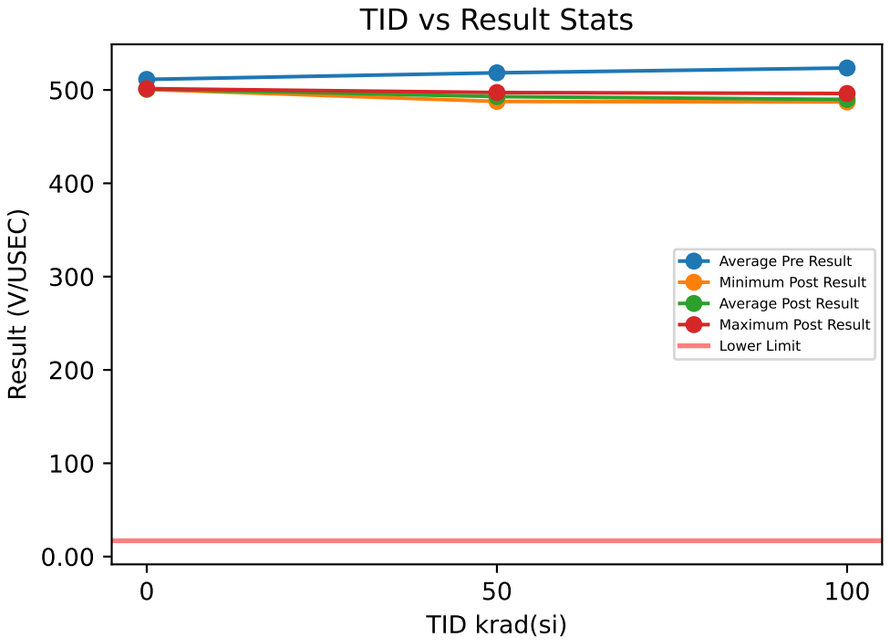
Test Results (Lower Limit = 17.0 (V/USEC))

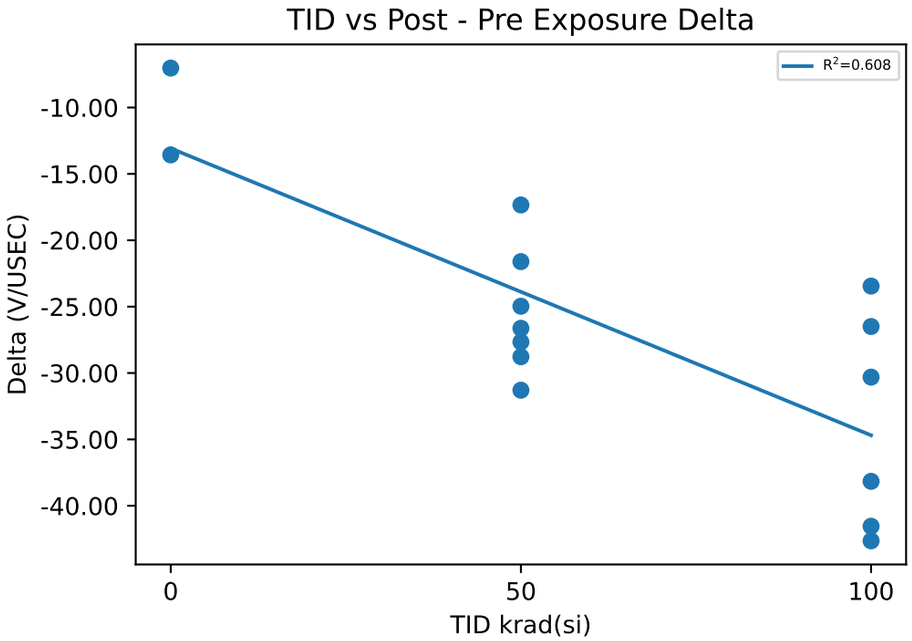
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	554.61	533.08	-21.536
89	50	Biased	564.78	531.77	-33.007
90	50	Biased	544.5	531.63	-12.871
92	50	Biased	557.29	524.62	-32.667
93	50	Unbiased	556.32	528.35	-27.967
94	50	Unbiased	557.07	529.92	-27.149
95	50	Unbiased	562.08	529.27	-32.816
96	100	Biased	557.83	530.57	-27.255
97	100	Biased	557.52	529.38	-28.141
98	100	Biased	552.85	530.34	-22.515
99	100	Unbiased	560.17	526.66	-33.517
100	100	Unbiased	552.74	527.35	-25.391
101	100	Unbiased	558.25	527.79	-30.452
102	0	Correlation	563.22	530.87	-32.35
103	0	Correlation	566.52	536.05	-30.469

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	563.22	564.87	566.52	2.3327	530.87	533.46	536.05	3.6628	-32.35	-31.409	-30.469	1.3301
50	544.5	556.67	564.78	6.4289	524.62	529.81	533.08	2.8045	-33.007	-26.859	-12.871	7.4423
100	552.74	556.56	560.17	3.0576	526.66	528.68	530.57	1.6395	-33.517	-27.879	-22.515	3.8426

Device Test: 19.28 PWRGD_SLEW_RATE_RISE(tsr_PWRGD_Rising/PWRGD/7/3/0/0/0/@PWRGD_SLEW_RATE_RISE)





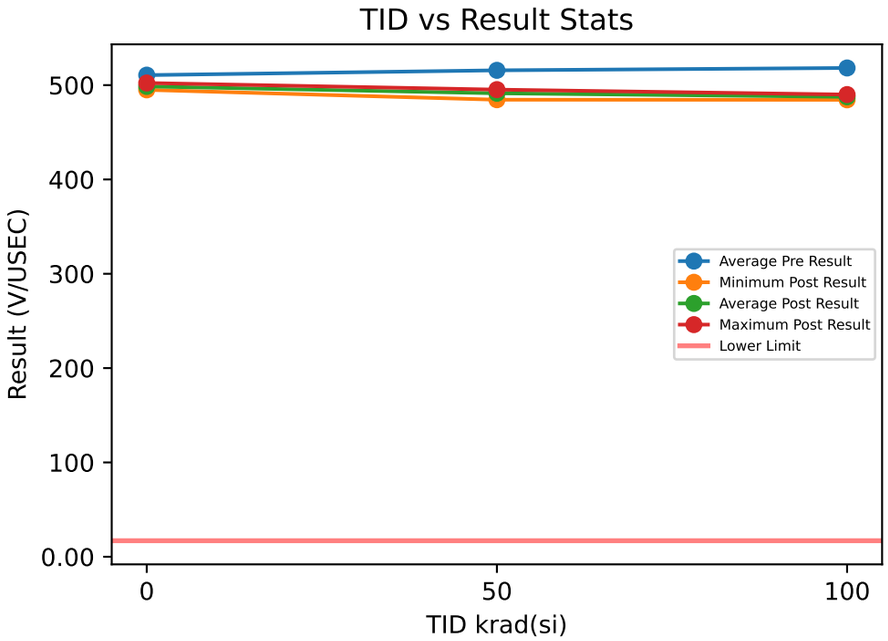
Test Results (Lower Limit = 17.0 (V/USEC))

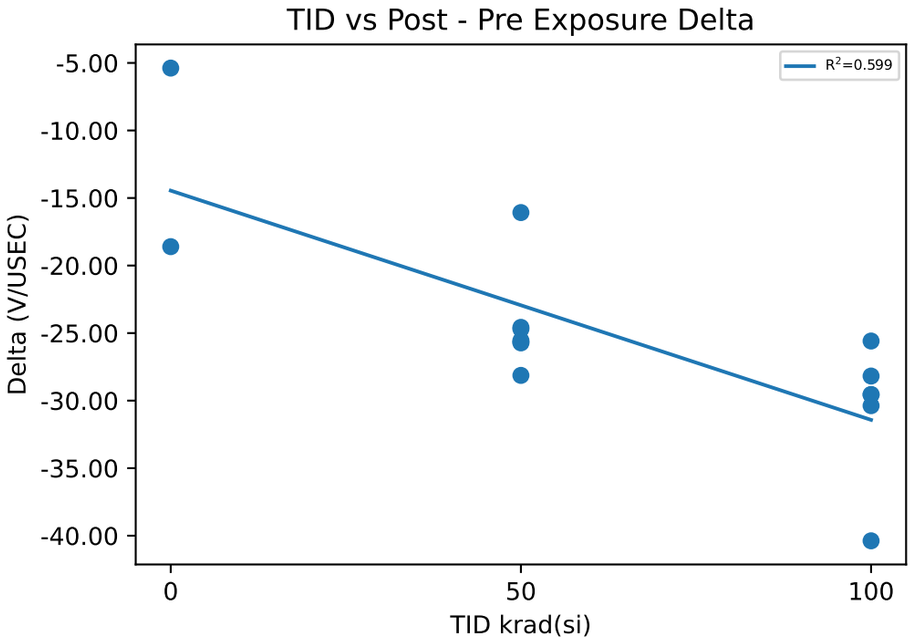
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	513.96	492.35	-21.608
89	50	Biased	515.34	488.71	-26.631
90	50	Biased	522.39	491.1	-31.294
92	50	Biased	516.51	487.74	-28.774
93	50	Unbiased	521.18	496.21	-24.971
94	50	Unbiased	524.93	497.26	-27.661
95	50	Unbiased	514.34	497	-17.34
96	100	Biased	531	489.46	-41.542
97	100	Biased	512.52	489.07	-23.452
98	100	Biased	530.64	488	-42.64
99	100	Unbiased	525.34	487.18	-38.158
100	100	Unbiased	522.73	496.23	-26.497
101	100	Unbiased	519.26	488.95	-30.309
102	0	Correlation	514.21	500.64	-13.569
103	0	Correlation	508.44	501.41	-7.029

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	508.44	511.33	514.21	4.0828	500.64	501.03	501.41	0.54164	-13.569	-10.299	-7.029	4.6245
50	513.96	518.38	524.93	4.3857	487.74	492.91	497.26	3.9697	-31.294	-25.468	-17.34	4.6948
100	512.52	523.58	531	7.0681	487.18	489.81	496.23	3.2517	-42.64	-33.766	-23.452	8.12

Device Test: 19.29 WDO_SLEW_RATE_RISE(tsr_WDOB_Rising/WDOB/7/3/0/0/0/@WDO_SLEW_RATE_RISE)





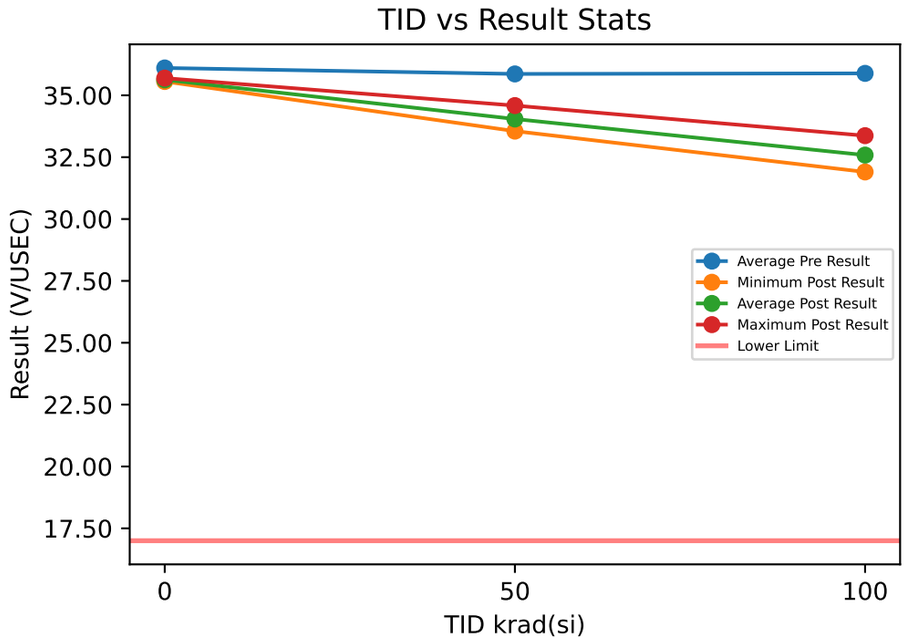
Test Results (Lower Limit = 17.0 (V/USEC))

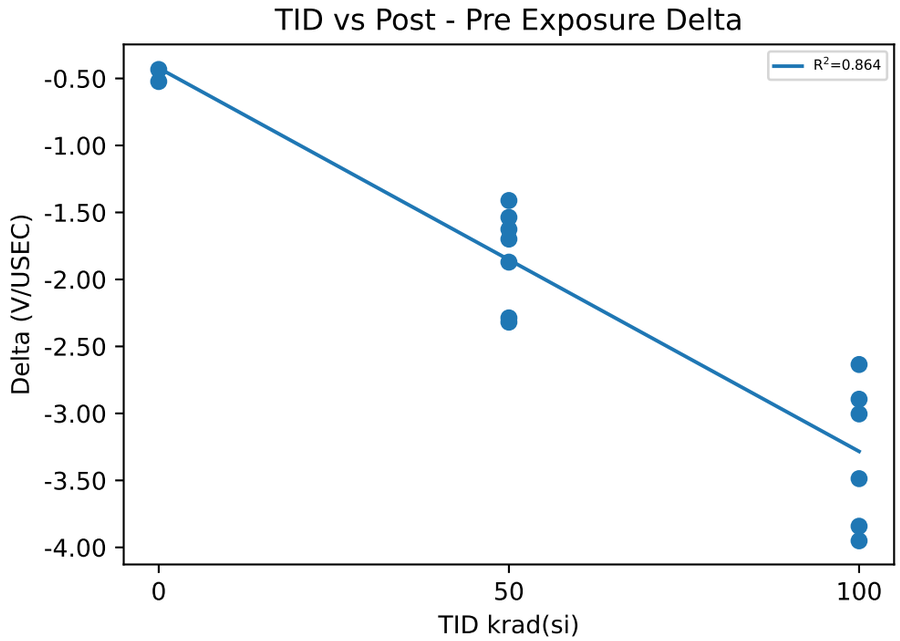
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	520.78	495.23	-25.548
89	50	Biased	518.77	494.07	-24.699
90	50	Biased	513.72	487.99	-25.726
92	50	Biased	510.19	484.52	-25.667
93	50	Unbiased	520.42	492.29	-28.132
94	50	Unbiased	518.07	493.49	-24.576
95	50	Unbiased	507.89	491.81	-16.078
96	100	Biased	513.52	487.94	-25.588
97	100	Biased	514.79	484.42	-30.374
98	100	Biased	515.84	486.29	-29.549
99	100	Unbiased	518.19	490	-28.181
100	100	Unbiased	518.89	489.33	-29.56
101	100	Unbiased	527.86	487.48	-40.379
102	0	Correlation	513.59	494.98	-18.602
103	0	Correlation	507.63	502.25	-5.381

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	507.63	510.61	513.59	4.2144	494.98	498.61	502.25	5.1343	-18.602	-11.992	-5.381	9.3487
50	507.89	515.69	520.78	5.1365	484.52	491.34	495.23	3.7858	-28.132	-24.347	-16.078	3.829
100	513.52	518.18	527.86	5.1532	484.42	487.57	490	2.0363	-40.379	-30.605	-25.588	5.0762

Device Test: 19.3 RESET_SLEW_RATE_RISE(tsr_RESETB4_Rising/RESETB4/1.6/3/0/0/0/@RESET_SLEW_RATE_RISE)





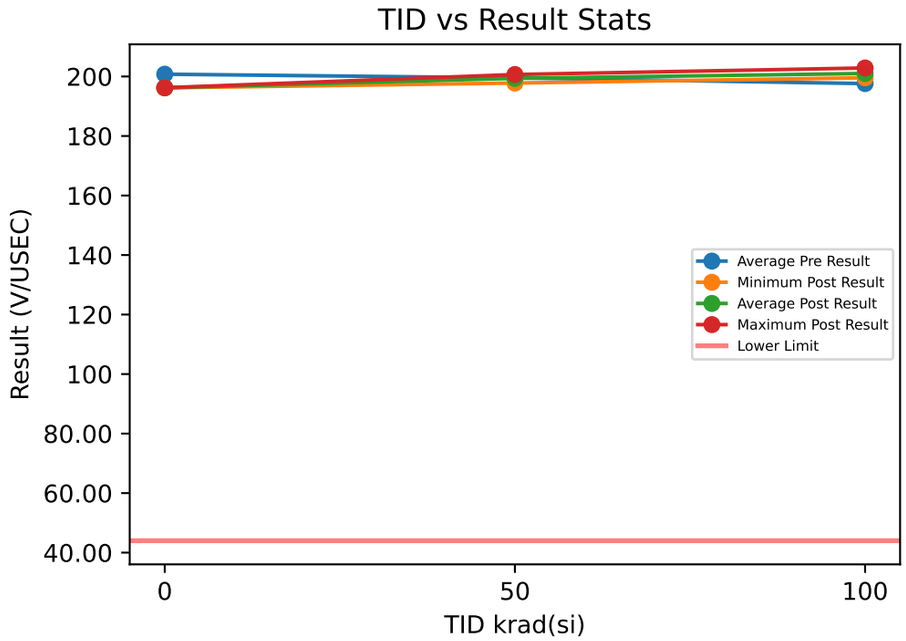
Test Results (Lower Limit = 17.0 (V/USEC))

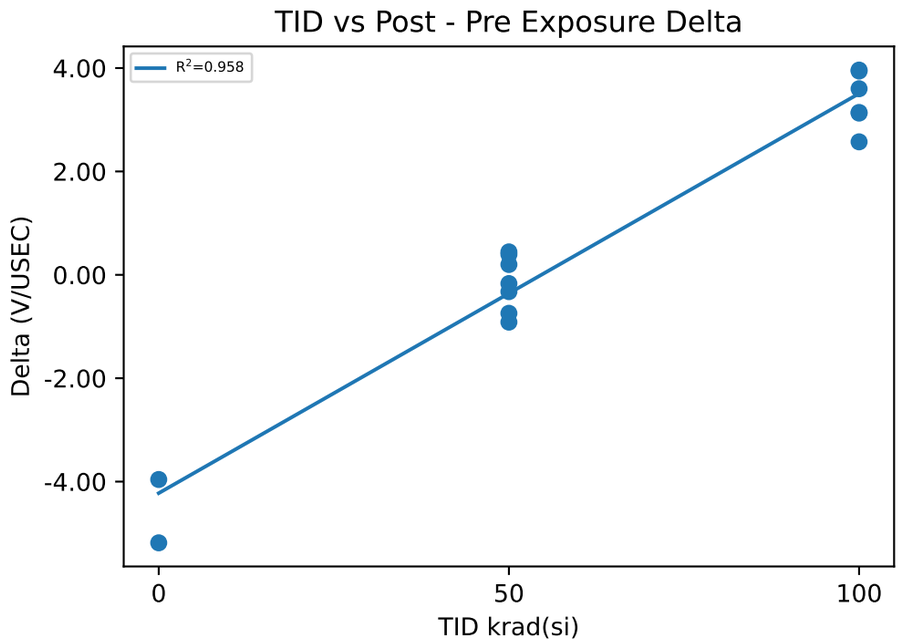
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	36.047	34.421	-1.626
89	50	Biased	36.122	34.585	-1.537
90	50	Biased	35.648	34.237	-1.411
92	50	Biased	35.405	33.706	-1.699
93	50	Unbiased	35.872	33.553	-2.319
94	50	Unbiased	36.292	34.005	-2.287
95	50	Unbiased	35.66	33.789	-1.871
96	100	Biased	36.004	33.369	-2.635
97	100	Biased	35.902	33.008	-2.894
98	100	Biased	36.074	33.07	-3.004
99	100	Unbiased	35.933	32.091	-3.842
100	100	Unbiased	35.55	32.063	-3.487
101	100	Unbiased	35.854	31.903	-3.951
102	0	Correlation	35.991	35.558	-0.433
103	0	Correlation	36.218	35.695	-0.523

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	35.991	36.105	36.218	0.16051	35.558	35.627	35.695	0.096874	-0.523	-0.478	-0.433	0.06364
50	35.405	35.864	36.292	0.31152	33.553	34.042	34.585	0.38599	-2.319	-1.8214	-1.411	0.35808
100	35.55	35.886	36.074	0.18202	31.903	32.584	33.369	0.63411	-3.951	-3.3022	-2.635	0.53799

Device Test: 19.30 RESET_SLEW_RATE_FALL(tsr_RESETB1_Falling/RESETB1/7/3/0/0/0/@RESET_SLEW_RATE_FALL)





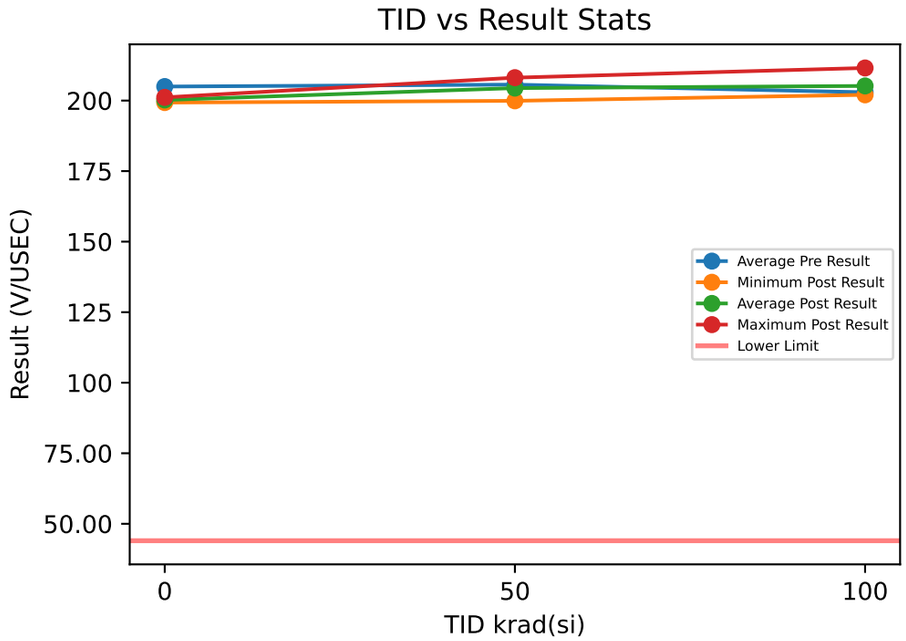
Test Results (Lower Limit = 44.0 (V/USEC))

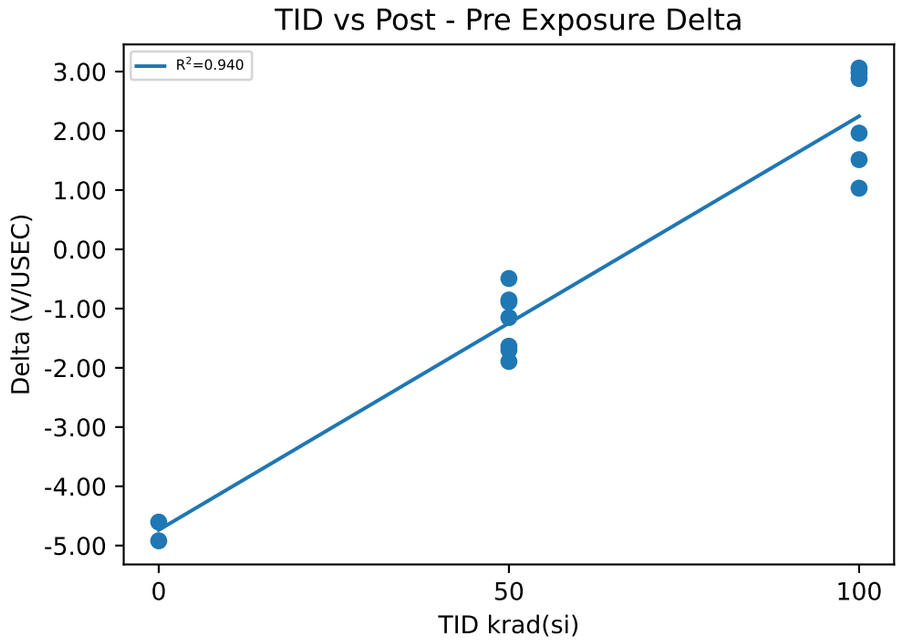
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	199.93	199.6	-0.325
89	50	Biased	200.46	200.66	0.2
90	50	Biased	199.56	199.95	0.395
92	50	Biased	199.46	198.71	-0.744
93	50	Unbiased	197.35	197.8	0.444
94	50	Unbiased	199.57	199.4	-0.169
95	50	Unbiased	200.41	199.5	-0.915
96	100	Biased	197.73	200.3	2.573
97	100	Biased	198.07	201.67	3.6
98	100	Biased	198.92	202.86	3.943
99	100	Unbiased	196.42	199.56	3.141
100	100	Unbiased	198.51	201.64	3.129
101	100	Unbiased	196.06	200.02	3.961
102	0	Correlation	200.15	196.19	-3.959
103	0	Correlation	201.4	196.21	-5.184

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	200.15	200.77	201.4	0.88388	196.19	196.2	196.21	0.017678	-5.184	-4.5715	-3.959	0.86621
50	197.35	199.53	200.46	1.0449	197.8	199.38	200.66	0.91107	-0.915	-0.15914	0.444	0.53864
100	196.06	197.62	198.92	1.1477	199.56	201.01	202.86	1.2533	2.573	3.3912	3.961	0.54287

Device Test: 19.31 RESET_SLEW_RATE_FALL(tsr_RESETB2_Falling/RESETB2/7/3/0/0/0/@RESET_SLEW_RATE_FALL)





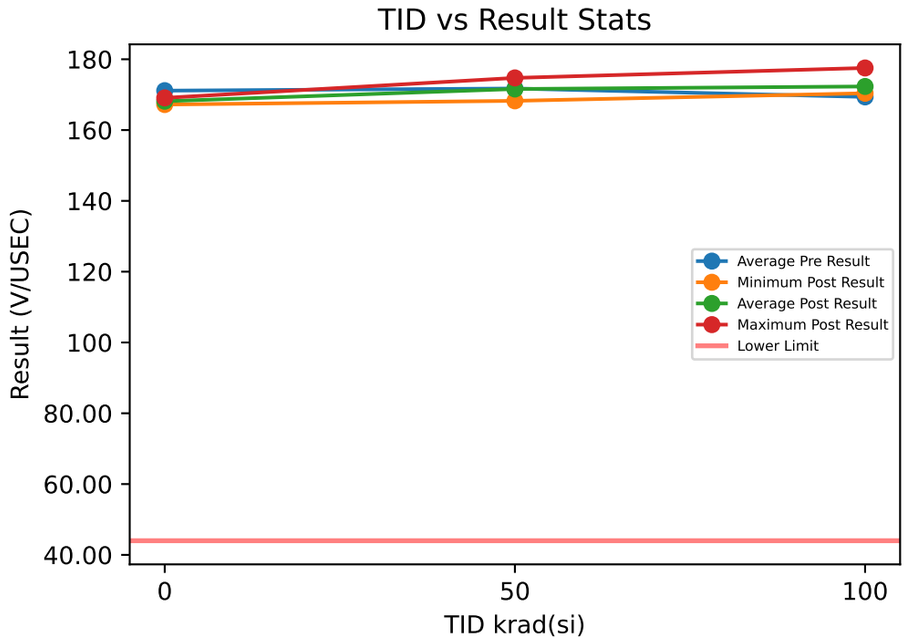
Test Results (Lower Limit = 44.0 (V/USEC))

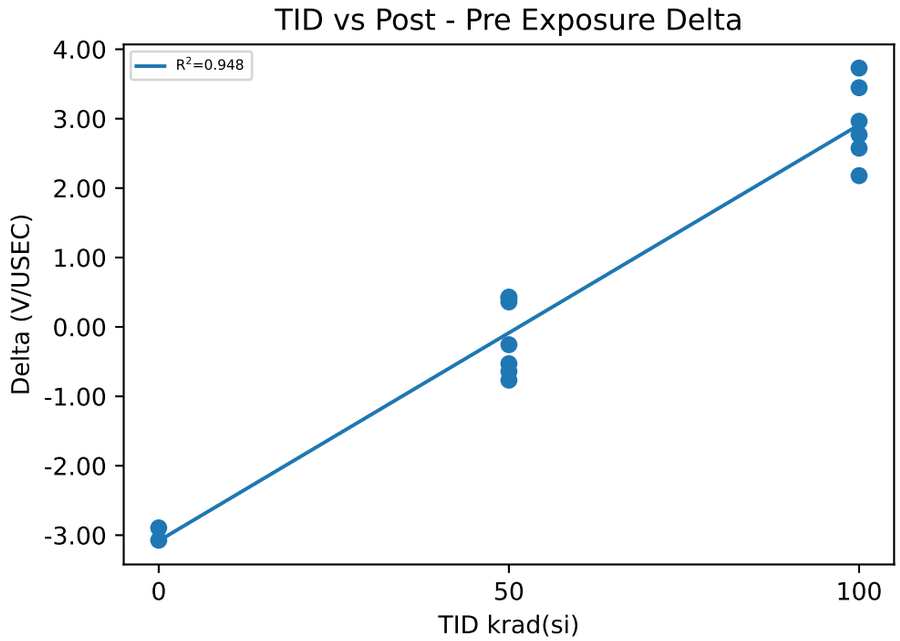
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	205.66	203.76	-1.893
89	50	Biased	209.82	208.12	-1.7
90	50	Biased	205.56	204.67	-0.889
92	50	Biased	207.68	207.19	-0.493
93	50	Unbiased	201.06	199.91	-1.151
94	50	Unbiased	207.33	205.7	-1.635
95	50	Unbiased	202.46	201.6	-0.856
96	100	Biased	203.38	204.9	1.514
97	100	Biased	200.07	202.03	1.961
98	100	Biased	210.52	211.55	1.032
99	100	Unbiased	201.29	204.17	2.882
100	100	Unbiased	201.64	204.62	2.979
101	100	Unbiased	200.78	203.84	3.059
102	0	Correlation	204.22	199.3	-4.92
103	0	Correlation	205.73	201.13	-4.604

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	204.22	204.97	205.73	1.072	199.3	200.21	201.13	1.2954	-4.92	-4.762	-4.604	0.22345
50	201.06	205.65	209.82	3.0432	199.91	204.42	208.12	2.9364	-1.893	-1.231	-0.493	0.52123
100	200.07	202.95	210.52	3.8727	202.03	205.19	211.55	3.2783	1.032	2.2378	3.059	0.85944

Device Test: 19.32 RESET_SLEW_RATE_FALL(tsr_RESETB3_Falling/RESETB3/7/3/0/0/0/@RESET_SLEW_RATE_FALL)





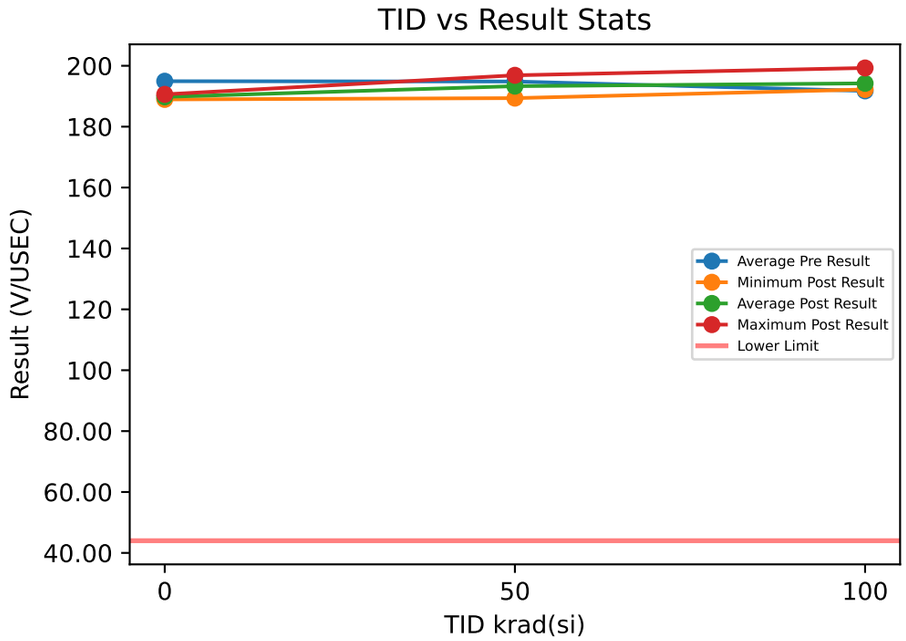
Test Results (Lower Limit = 44.0 (V/USEC))

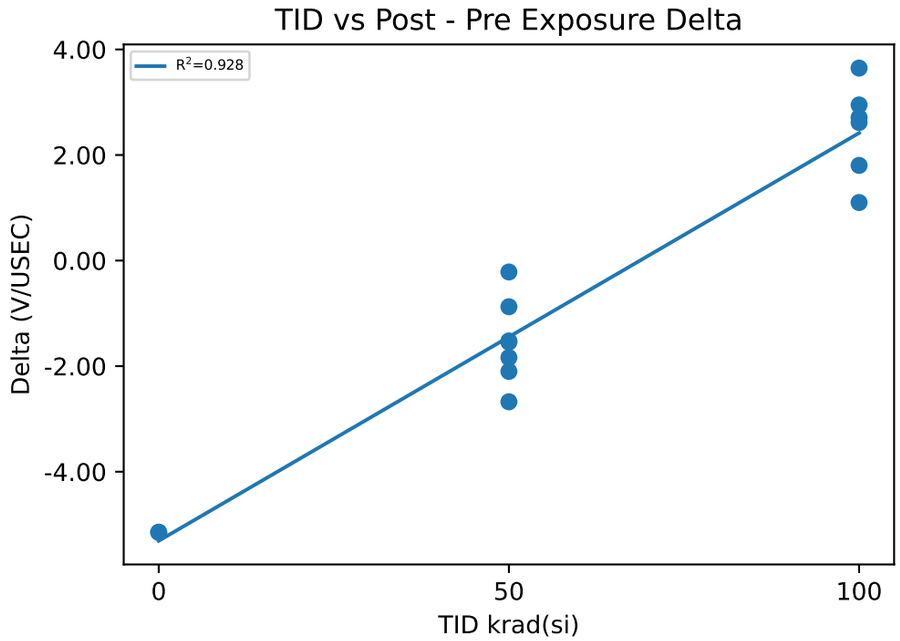
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	171.58	171.32	-0.256
89	50	Biased	174.3	174.73	0.429
90	50	Biased	172.44	171.67	-0.767
92	50	Biased	173.97	173.44	-0.53
93	50	Unbiased	167.84	168.26	0.42
94	50	Unbiased	173.52	172.88	-0.641
95	50	Unbiased	168.54	168.9	0.36
96	100	Biased	169.89	172.66	2.77
97	100	Biased	167.43	170.39	2.963
98	100	Biased	174.09	177.54	3.446
99	100	Unbiased	168.05	170.63	2.575
100	100	Unbiased	169.57	171.75	2.179
101	100	Unbiased	167.17	170.9	3.729
102	0	Correlation	170.29	167.21	-3.073
103	0	Correlation	171.98	169.09	-2.895

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	170.29	171.13	171.98	1.2	167.21	168.15	169.09	1.3258	-3.073	-2.984	-2.895	0.12587
50	167.84	171.74	174.3	2.603	168.26	171.6	174.73	2.3573	-0.767	-0.14071	0.429	0.53183
100	167.17	169.37	174.09	2.5677	170.39	172.31	177.54	2.6937	2.179	2.9437	3.729	0.56925

Device Test: 19.33 RESET_SLEW_RATE_FALL(tsr_RESETB4_Falling/RESETB4/7/3/0/0/0/@RESET_SLEW_RATE_FALL)





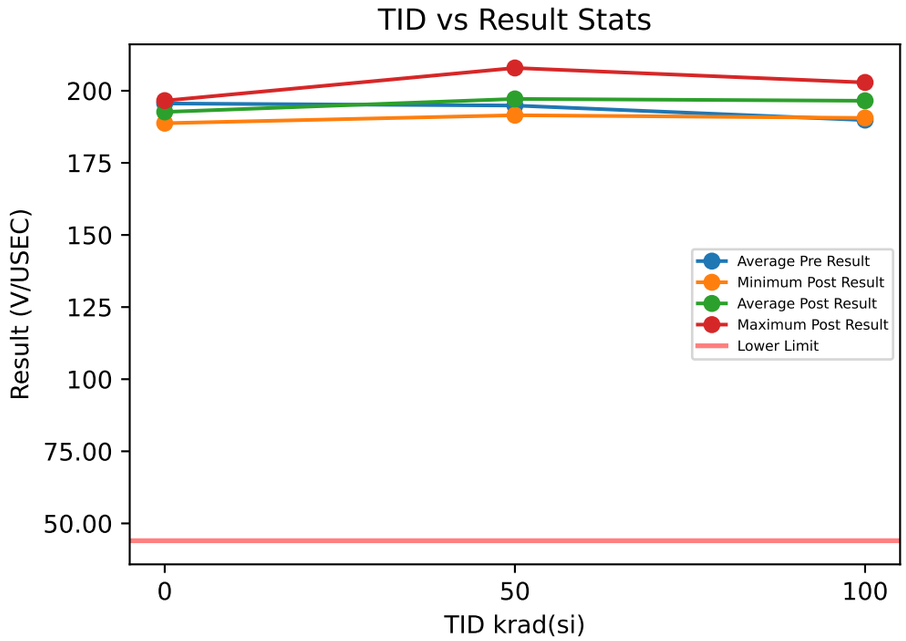
Test Results (Lower Limit = 44.0 (V/USEC))

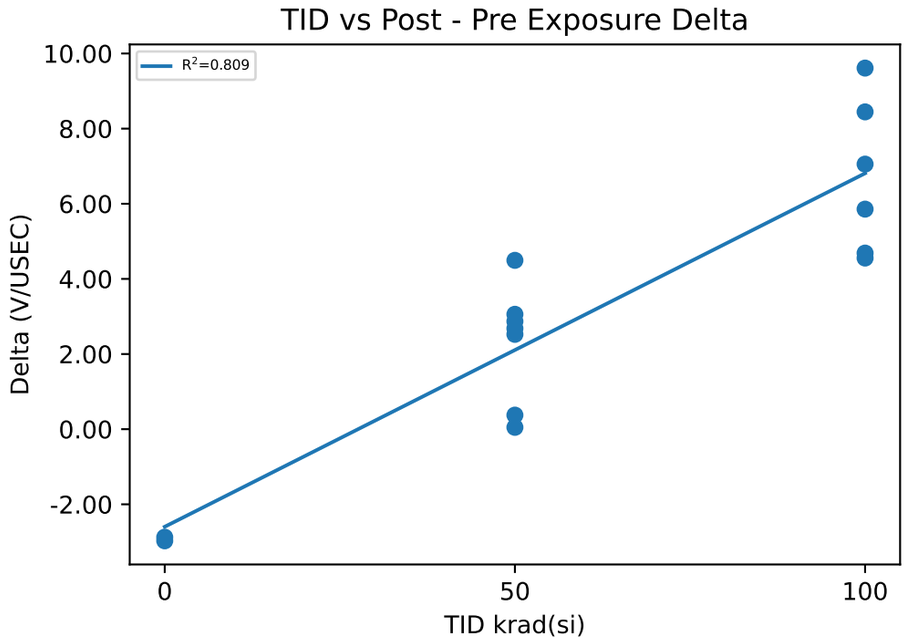
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	194.85	193.01	-1.837
89	50	Biased	198.97	196.87	-2.099
90	50	Biased	194.75	193.21	-1.544
92	50	Biased	196.28	194.75	-1.523
93	50	Unbiased	189.59	189.37	-0.216
94	50	Unbiased	198.3	195.63	-2.675
95	50	Unbiased	191.15	190.27	-0.875
96	100	Biased	192.95	194.75	1.803
97	100	Biased	189.81	192.52	2.711
98	100	Biased	196.66	199.28	2.616
99	100	Unbiased	188.56	192.21	3.647
100	100	Unbiased	193.13	194.23	1.1
101	100	Unbiased	189.38	192.32	2.949
102	0	Correlation	194.1	188.95	-5.149
103	0	Correlation	195.76	190.62	-5.146

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	194.1	194.93	195.76	1.1752	188.95	189.78	190.62	1.1773	-5.149	-5.1475	-5.146	0.0021213
50	189.59	194.84	198.97	3.4724	189.37	193.3	196.87	2.7378	-2.675	-1.5384	-0.216	0.80461
100	188.56	191.75	196.66	3.0671	192.21	194.22	199.28	2.6974	1.1	2.471	3.647	0.89621

Device Test: 19.34 PWRGD_SLEW_RATE_FALL(tsr_PWRGD_Falling/PWRGD/7/3/0/0/0/@PWRGD_SLEW_RATE_FALL)





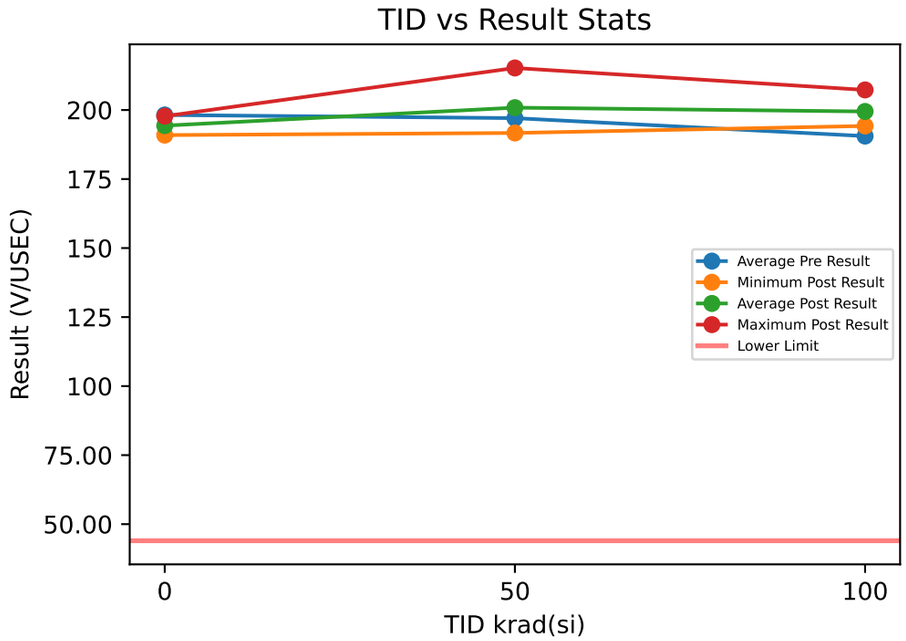
Test Results (Lower Limit = 44.0 (V/USEC))

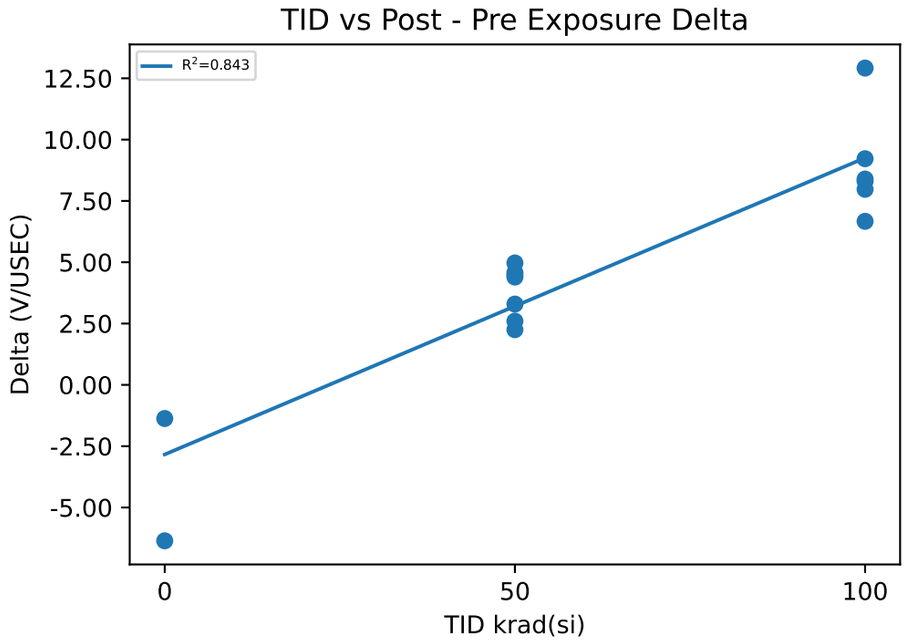
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	191.9	194.77	2.87
89	50	Biased	197.87	200.39	2.524
90	50	Biased	193.6	193.65	0.049
92	50	Biased	198.03	198.41	0.374
93	50	Unbiased	190.5	193.56	3.058
94	50	Unbiased	203.41	207.9	4.494
95	50	Unbiased	188.83	191.51	2.682
96	100	Biased	191.49	197.35	5.857
97	100	Biased	190.6	197.66	7.055
98	100	Biased	193.27	202.88	9.612
99	100	Unbiased	185.89	190.58	4.687
100	100	Unbiased	192.47	197.03	4.555
101	100	Unbiased	185.26	193.71	8.446
102	0	Correlation	191.63	188.75	-2.876
103	0	Correlation	199.55	196.57	-2.972

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	191.63	195.59	199.55	5.5996	188.75	192.66	196.57	5.5317	-2.972	-2.924	-2.876	0.067882
50	188.83	194.88	203.41	5.1287	191.51	197.17	207.9	5.6305	0.049	2.293	4.494	1.5645
100	185.26	189.83	193.27	3.4219	190.58	196.53	202.88	4.1448	4.555	6.702	9.612	2.0503

Device Test: 19.35 WDO_SLEW_RATE_FALL(tsr_WDOB_Falling/WDOB/7/3/0/0/0/@WDO_SLEW_RATE_FALL)





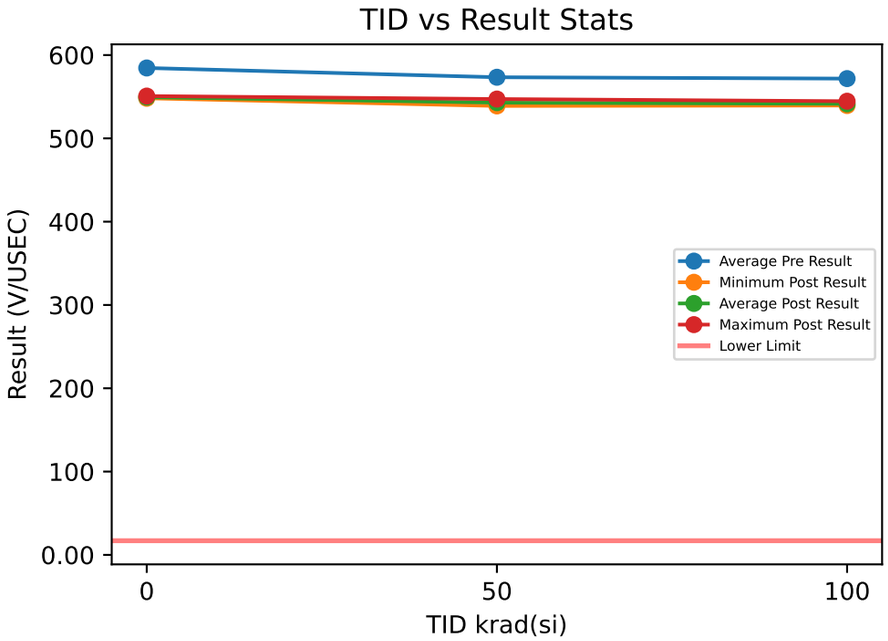
Test Results (Lower Limit = 44.0 (V/USEC))

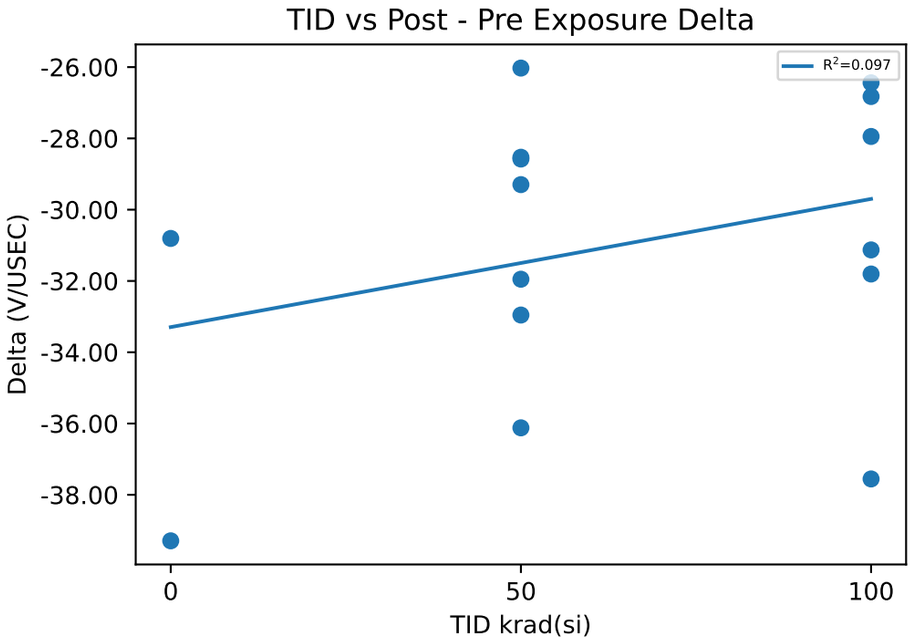
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	193.57	197.97	4.396
89	50	Biased	202.29	206.78	4.485
90	50	Biased	193.34	196.63	3.294
92	50	Biased	196.87	201.44	4.579
93	50	Unbiased	193.64	196.24	2.599
94	50	Unbiased	210.26	215.23	4.97
95	50	Unbiased	189.44	191.69	2.25
96	100	Biased	192.91	201.31	8.392
97	100	Biased	193.14	201.44	8.303
98	100	Biased	194.36	207.28	12.917
99	100	Unbiased	186.24	194.22	7.975
100	100	Unbiased	189.16	198.38	9.221
101	100	Unbiased	187.56	194.23	6.668
102	0	Correlation	192.29	190.92	-1.372
103	0	Correlation	204.12	197.76	-6.359

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.29	198.21	204.12	8.3693	190.92	194.34	197.76	4.843	-6.359	-3.8655	-1.372	3.5263
50	189.44	197.06	210.26	7.0401	191.69	200.85	215.23	7.8896	2.25	3.7961	4.97	1.0725
100	186.24	190.56	194.36	3.3546	194.22	199.48	207.28	4.9906	6.668	8.9127	12.917	2.1303

Device Test: 19.36 RESET_SLEW_RATE_RISE(tsr_RESETB1_Rising/RESETB1/7/14/0/0/0/@RESET_SLEW_RATE_RISE)





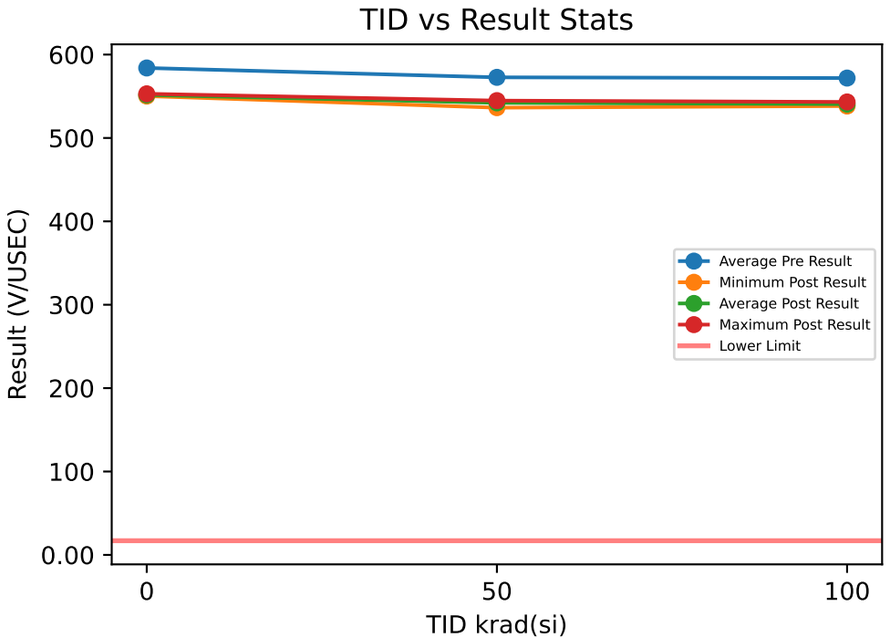
Test Results (Lower Limit = 17.0 (V/USEC))

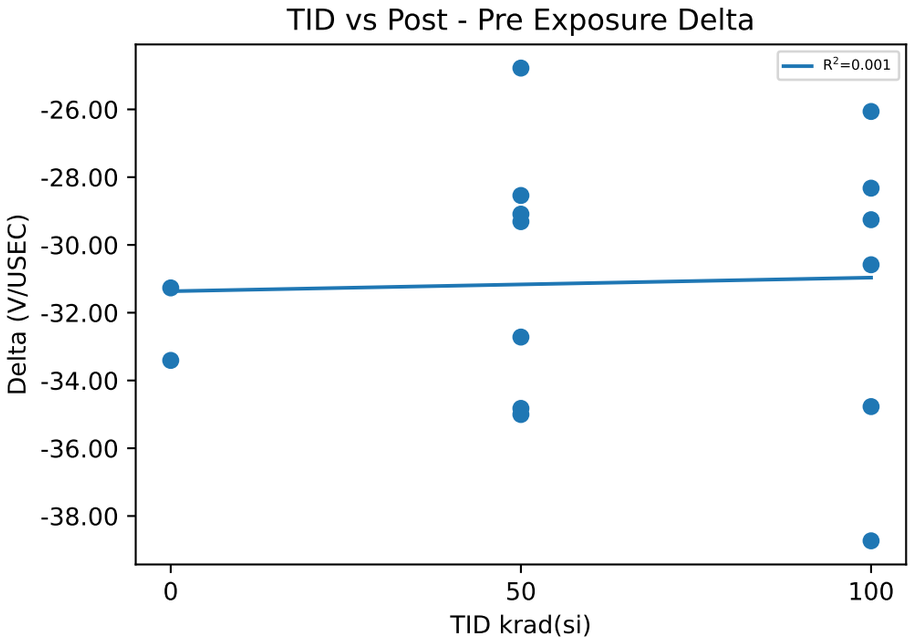
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	578.9	542.78	-36.121
89	50	Biased	569.32	540.79	-28.529
90	50	Biased	572.49	543.19	-29.297
92	50	Biased	570.89	538.94	-31.951
93	50	Unbiased	571.01	544.98	-26.027
94	50	Unbiased	575.13	542.18	-32.956
95	50	Unbiased	575.78	547.2	-28.579
96	100	Biased	570.58	539.45	-31.129
97	100	Biased	571.42	544.6	-26.825
98	100	Biased	572.54	540.73	-31.805
99	100	Unbiased	569.29	541.34	-27.946
100	100	Unbiased	579.21	541.65	-37.555
101	100	Unbiased	567.4	540.96	-26.44
102	0	Correlation	581.58	550.77	-30.807
103	0	Correlation	587.42	548.13	-39.291

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	581.58	584.5	587.42	4.1323	548.13	549.45	550.77	1.8668	-39.291	-35.049	-30.807	5.9991
50	569.32	573.36	578.9	3.3744	538.94	542.87	547.2	2.6942	-36.121	-30.494	-26.027	3.3853
100	567.4	571.74	579.21	4.0661	539.45	541.46	544.6	1.7155	-37.555	-30.283	-26.44	4.1977

Device Test: 19.37 RESET_SLEW_RATE_RISE(tsr_RESETB2_Rising/RESETB2/7/14/0/0/0/@RESET_SLEW_RATE_RISE)





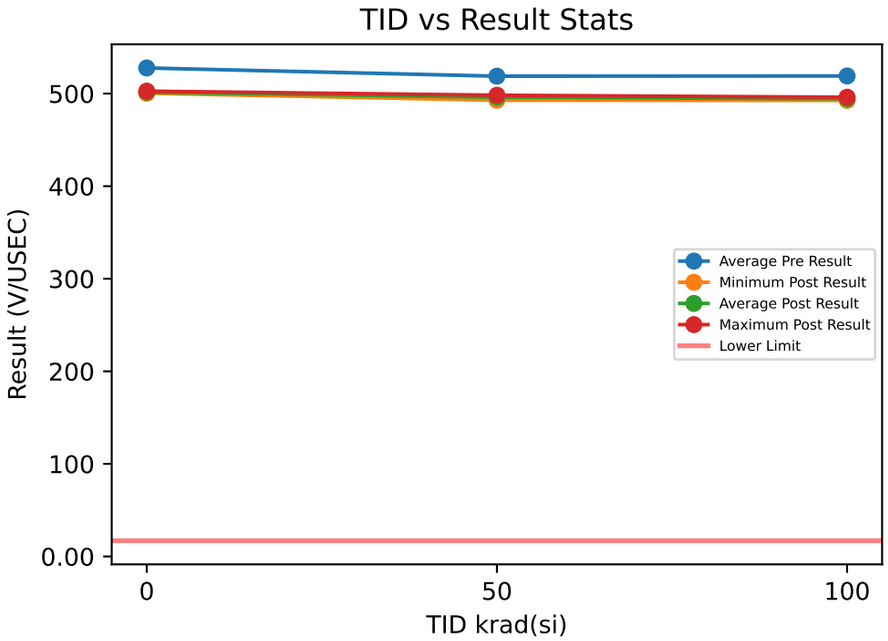
Test Results (Lower Limit = 17.0 (V/USEC))

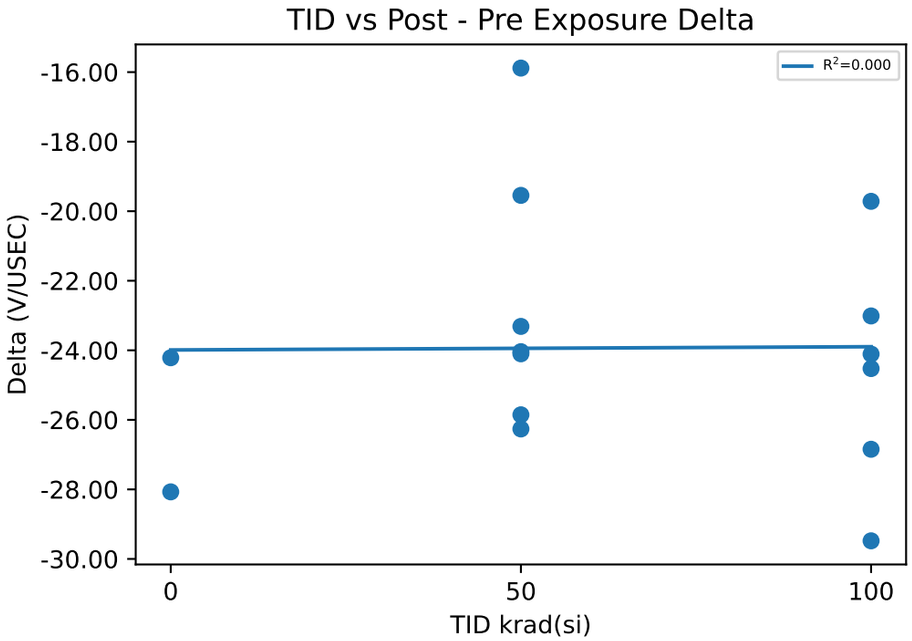
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	579.61	544.79	-34.824
89	50	Biased	570.85	541.76	-29.091
90	50	Biased	566.15	541.37	-24.781
92	50	Biased	565.64	536.32	-29.313
93	50	Unbiased	575.31	542.59	-32.719
94	50	Unbiased	572.26	543.72	-28.541
95	50	Unbiased	579.09	544.09	-35.004
96	100	Biased	567.56	538.3	-29.256
97	100	Biased	565.82	539.75	-26.062
98	100	Biased	570.12	541.8	-28.325
99	100	Unbiased	571.19	540.6	-30.585
100	100	Unbiased	578.36	539.63	-38.732
101	100	Unbiased	577.96	543.19	-34.771
102	0	Correlation	581.5	550.23	-31.268
103	0	Correlation	586.37	552.96	-33.408

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	581.5	583.94	586.37	3.4429	550.23	551.6	552.96	1.9297	-33.408	-32.338	-31.268	1.5132
50	565.64	572.7	579.61	5.655	536.32	542.09	544.79	2.8302	-35.004	-30.61	-24.781	3.7363
100	565.82	571.83	578.36	5.2527	538.3	540.55	543.19	1.7363	-38.732	-31.289	-26.062	4.6531

Device Test: 19.38 RESET_SLEW_RATE_RISE(tsr_RESETB3_Rising/RESETB3/7/14/0/0/0/@RESET_SLEW_RATE_RISE)





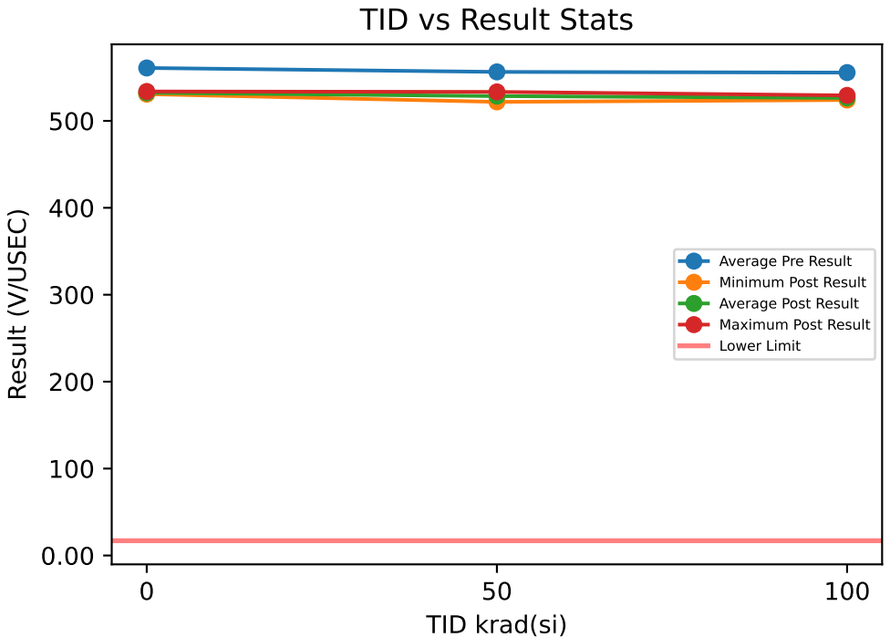
Test Results (Lower Limit = 17.0 (V/USEC))

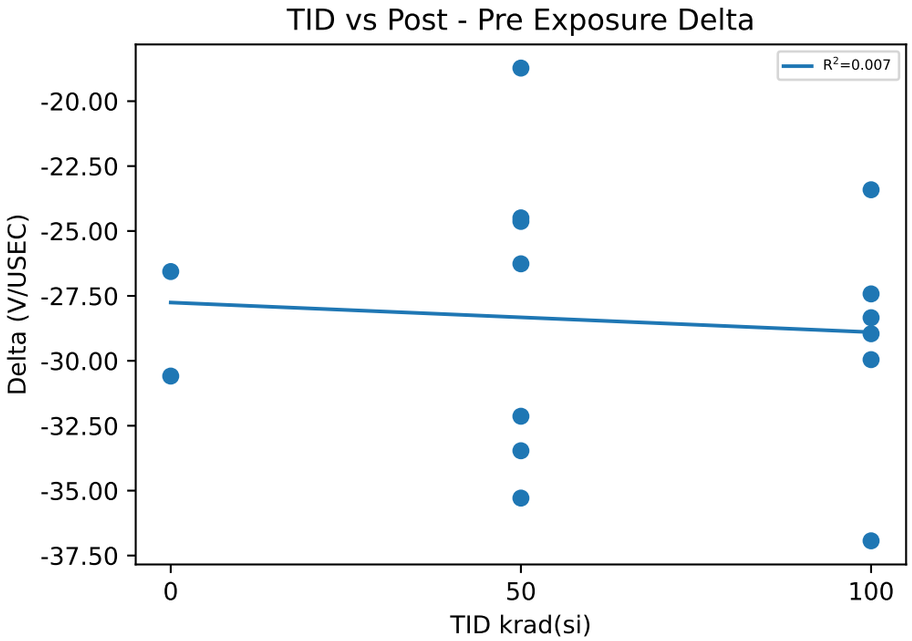
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	522.24	498.14	-24.101
89	50	Biased	523.4	497.14	-26.262
90	50	Biased	509.99	494.1	-15.884
92	50	Biased	516.89	492.85	-24.039
93	50	Unbiased	517.79	498.25	-19.545
94	50	Unbiased	521.9	496.04	-25.855
95	50	Unbiased	519.61	496.3	-23.313
96	100	Biased	518.91	494.38	-24.525
97	100	Biased	518.98	494.87	-24.109
98	100	Biased	514.15	494.44	-19.716
99	100	Unbiased	515.67	492.66	-23.012
100	100	Unbiased	522.93	496.09	-26.846
101	100	Unbiased	523.73	494.25	-29.479
102	0	Correlation	528.5	500.43	-28.071
103	0	Correlation	526.89	502.68	-24.214

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	526.89	527.69	528.5	1.1356	500.43	501.55	502.68	1.5917	-28.071	-26.142	-24.214	2.7273
50	509.99	518.83	523.4	4.5747	492.85	496.12	498.25	2.0176	-26.262	-22.714	-15.884	3.7234
100	514.15	519.06	523.73	3.805	492.66	494.45	496.09	1.1045	-29.479	-24.614	-19.716	3.3308

Device Test: 19.39 RESET_SLEW_RATE_RISE(tsr_RESETB4_Rising/RESETB4/7/14/0/0/0/@RESET_SLEW_RATE_RISE)





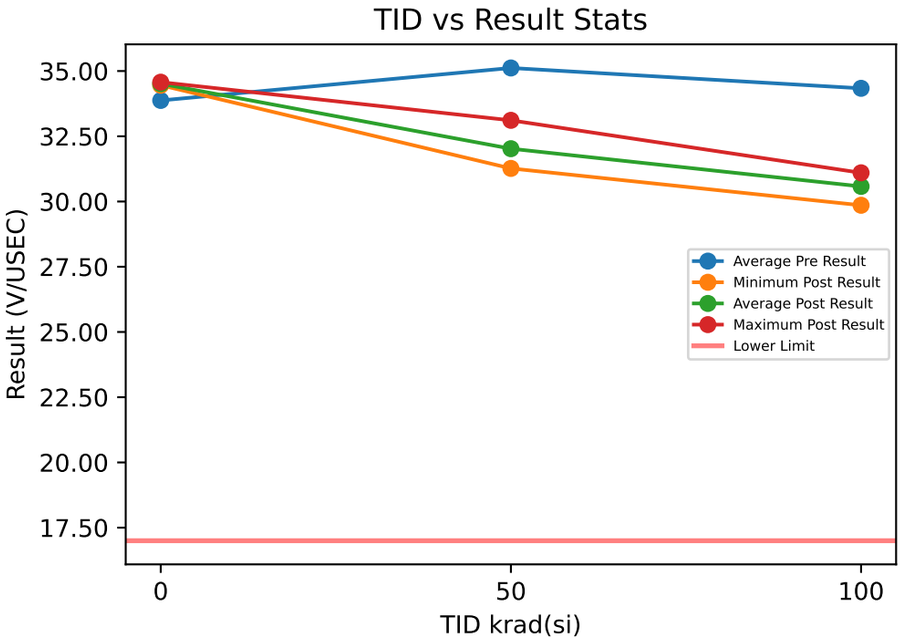
Test Results (Lower Limit = 17.0 (V/USEC))

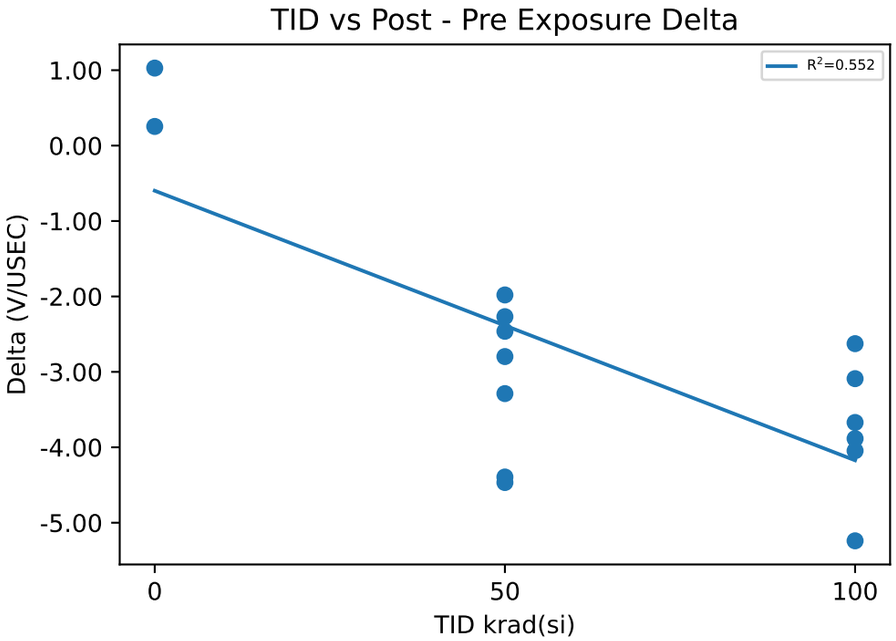
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	555.1	530.47	-24.631
89	50	Biased	552.06	533.34	-18.725
90	50	Biased	553.7	529.2	-24.494
92	50	Biased	554	521.87	-32.135
93	50	Unbiased	562.57	527.28	-35.287
94	50	Unbiased	562.71	529.25	-33.464
95	50	Unbiased	554.29	528.02	-26.264
96	100	Biased	559.26	529.31	-29.955
97	100	Biased	555.74	528.32	-27.423
98	100	Biased	550.31	526.9	-23.412
99	100	Unbiased	554.76	525.8	-28.958
100	100	Unbiased	552.38	524.04	-28.34
101	100	Unbiased	560.94	524.01	-36.933
102	0	Correlation	561.36	530.77	-30.588
103	0	Correlation	560.38	533.82	-26.562

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	560.38	560.87	561.36	0.69155	530.77	532.29	533.82	2.1553	-30.588	-28.575	-26.562	2.8468
50	552.06	556.35	562.71	4.3943	521.87	528.49	533.34	3.5137	-35.287	-27.857	-18.725	5.9525
100	550.31	555.57	560.94	4.0241	524.01	526.4	529.31	2.1919	-36.933	-29.17	-23.412	4.4231

Device Test: 19.4 PWRGD_SLEW_RATE_RISE(tsr_PWRGD_Rising/PWRGD/1.6/3/0/0/0/@PWRGD_SLEW_RATE_RISE)





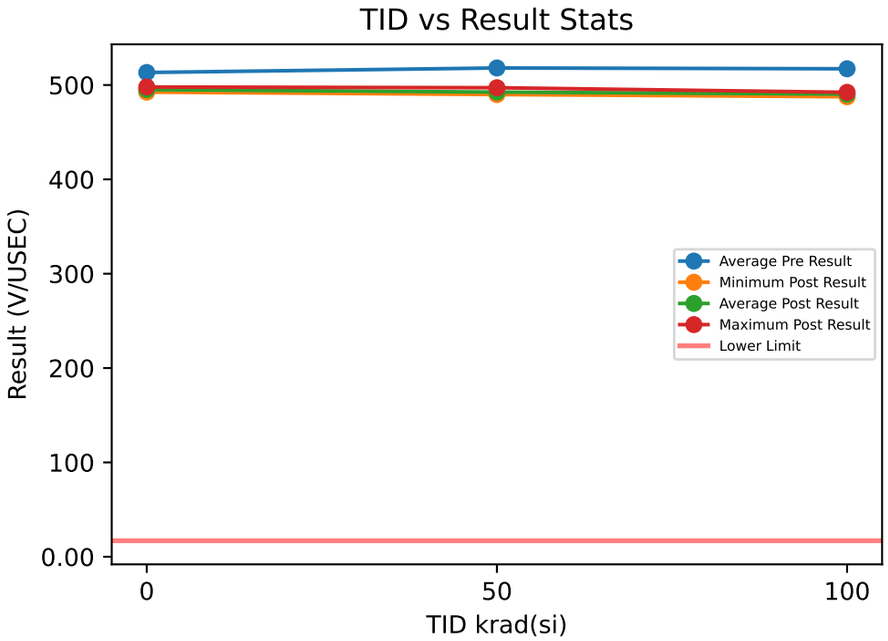
Test Results (Lower Limit = 17.0 (V/USEC))

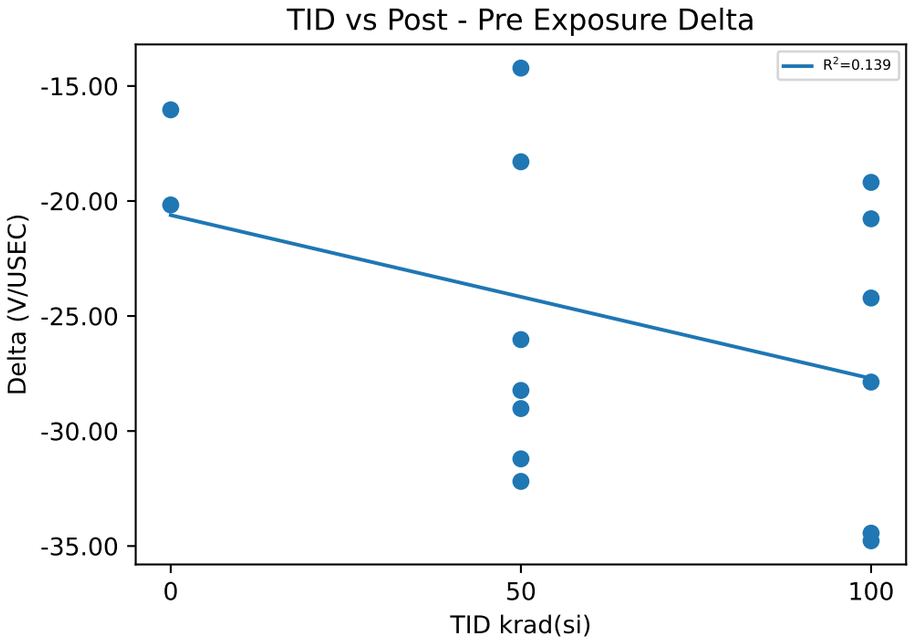
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	34.184	31.916	-2.268
89	50	Biased	36.234	31.84	-4.394
90	50	Biased	36.28	31.813	-4.467
92	50	Biased	33.73	31.268	-2.462
93	50	Unbiased	34.896	32.099	-2.797
94	50	Unbiased	36.399	33.111	-3.288
95	50	Unbiased	34.099	32.119	-1.98
96	100	Biased	36.231	30.991	-5.24
97	100	Biased	33.812	29.927	-3.885
98	100	Biased	33.902	29.856	-4.046
99	100	Unbiased	34.376	30.705	-3.671
100	100	Unbiased	34.19	31.1	-3.09
101	100	Unbiased	33.516	30.89	-2.626
102	0	Correlation	34.202	34.456	0.254
103	0	Correlation	33.545	34.573	1.028

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	33.545	33.873	34.202	0.46457	34.456	34.514	34.573	0.082731	0.254	0.641	1.028	0.5473
50	33.73	35.117	36.399	1.1636	31.268	32.024	33.111	0.55645	-4.467	-3.0937	-1.98	1.002
100	33.516	34.338	36.231	0.9746	29.856	30.578	31.1	0.54802	-5.24	-3.7597	-2.626	0.89784

Device Test: 19.40 PWRGD_SLEW_RATE_RISE(tsr_PWRGD_Rising/PWRGD/7/14/0/0/0/@PWRGD_SLEW_RATE_RISE)





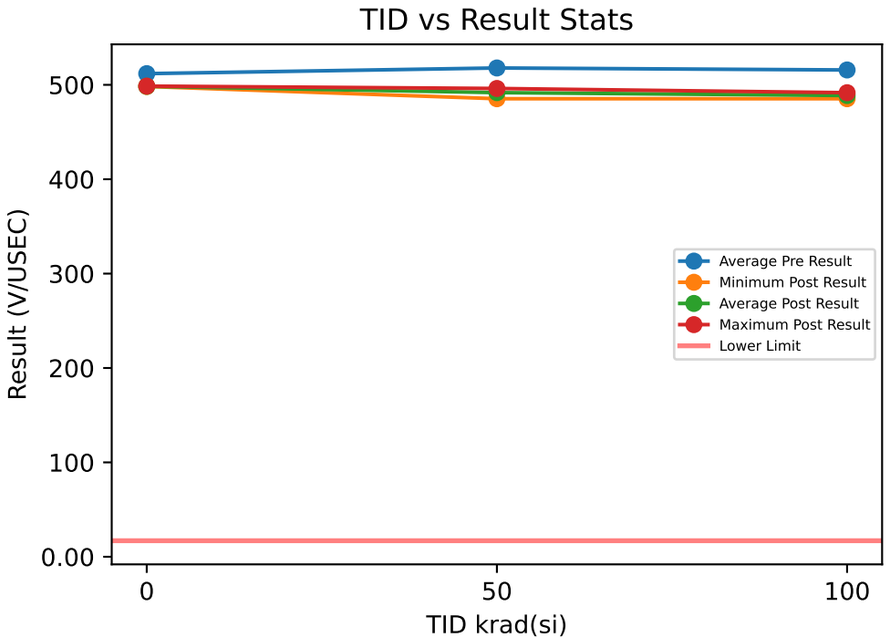
Test Results (Lower Limit = 17.0 (V/USEC))

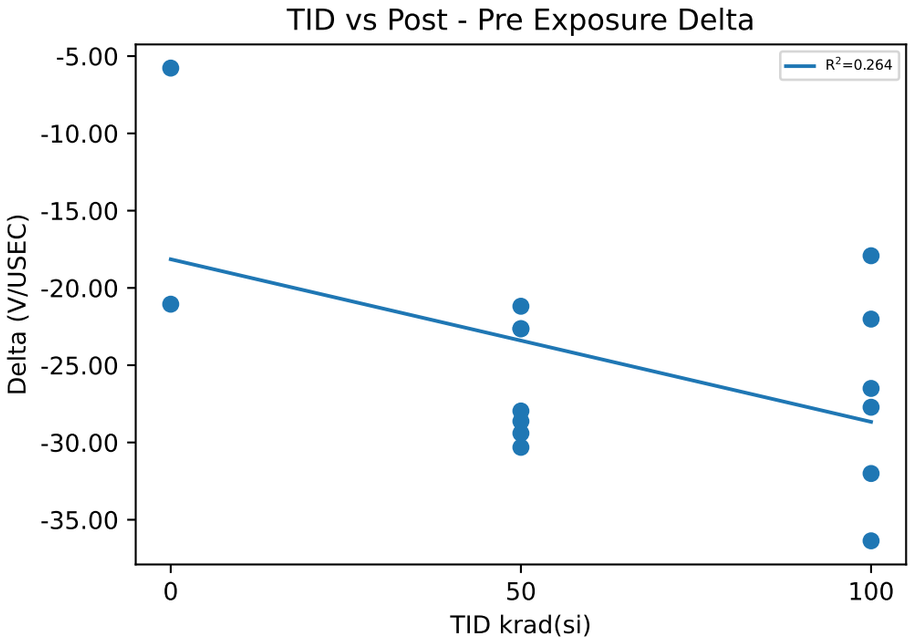
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	521.39	490.18	-31.21
89	50	Biased	518.92	489.9	-29.023
90	50	Biased	525.77	493.58	-32.19
92	50	Biased	515.97	489.94	-26.026
93	50	Unbiased	522.54	494.3	-28.236
94	50	Unbiased	510.55	492.25	-18.295
95	50	Unbiased	511.36	497.14	-14.221
96	100	Biased	511.68	490.91	-20.773
97	100	Biased	511.45	492.26	-19.19
98	100	Biased	524.89	490.45	-34.44
99	100	Unbiased	513.9	489.69	-24.218
100	100	Unbiased	522.33	487.56	-34.773
101	100	Unbiased	519.05	491.18	-27.872
102	0	Correlation	512.63	492.46	-20.172
103	0	Correlation	513.92	497.88	-16.036

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	512.63	513.28	513.92	0.90793	492.46	495.17	497.88	3.8325	-20.172	-18.104	-16.036	2.9246
50	510.55	518.07	525.77	5.7317	489.9	492.47	497.14	2.7285	-32.19	-25.6	-14.221	6.7896
100	511.45	517.22	524.89	5.7163	487.56	490.34	492.26	1.6055	-34.773	-26.878	-19.19	6.6926

Device Test: 19.41 WDO_SLEW_RATE_RISE(tsr_WDOB_Rising/WDOB/7/14/0/0/0/@WDO_SLEW_RATE_RISE)





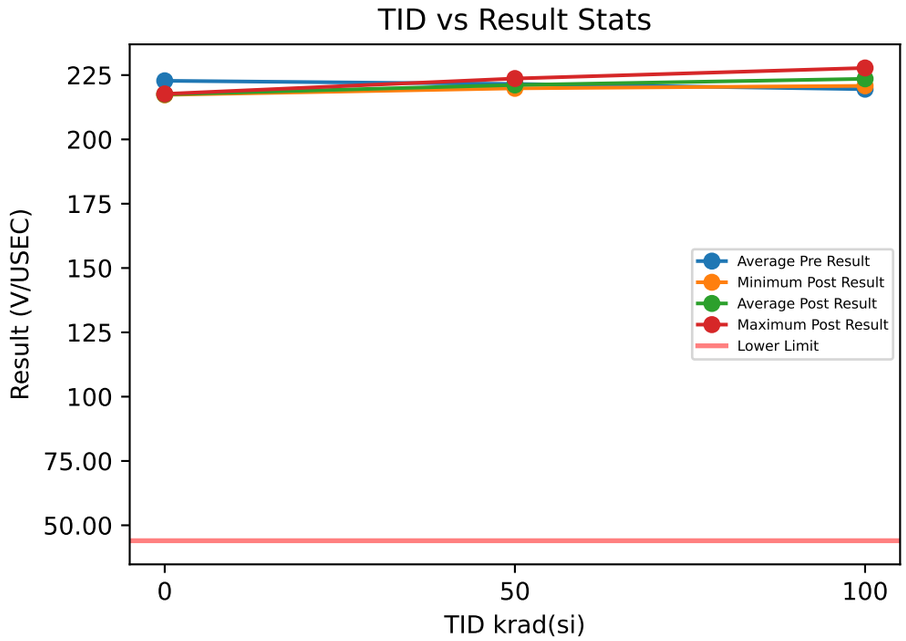
Test Results (Lower Limit = 17.0 (V/USEC))

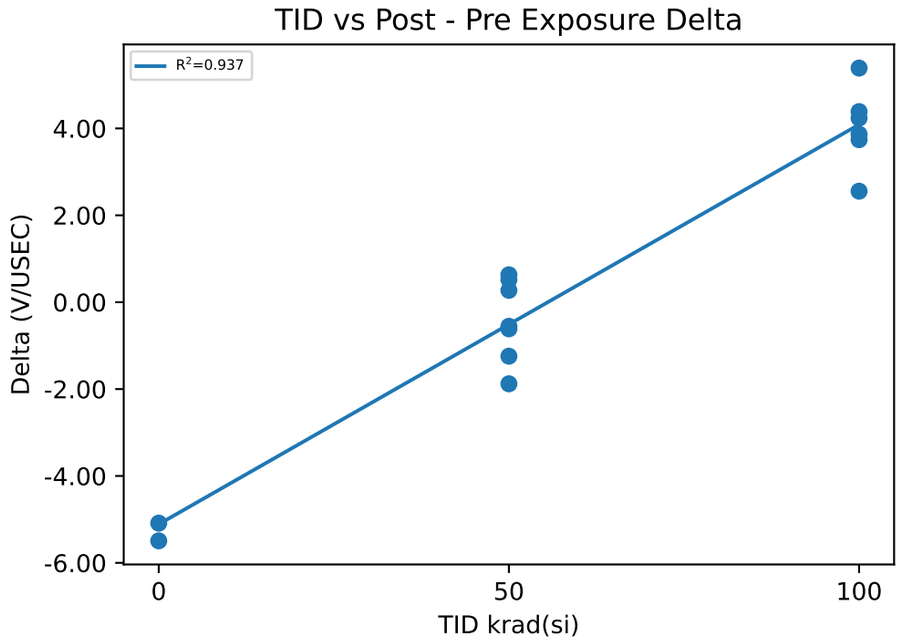
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	518.78	496.14	-22.642
89	50	Biased	520.04	492.08	-27.963
90	50	Biased	520.38	490.06	-30.314
92	50	Biased	514.69	485.28	-29.404
93	50	Unbiased	520.52	491.89	-28.627
94	50	Unbiased	514.13	492.95	-21.185
95	50	Unbiased	516.52	493.88	-22.639
96	100	Biased	518.58	490.86	-27.72
97	100	Biased	509.59	491.67	-17.918
98	100	Biased	510.35	488.33	-22.017
99	100	Unbiased	521.64	485.28	-36.364
100	100	Unbiased	513.09	486.58	-26.503
101	100	Unbiased	521.3	489.3	-32.009
102	0	Correlation	519.7	498.65	-21.052
103	0	Correlation	504.05	498.28	-5.774

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	504.05	511.88	519.7	11.067	498.28	498.46	498.65	0.26375	-21.052	-13.413	-5.774	10.803
50	514.13	517.87	520.52	2.7317	485.28	491.76	496.14	3.4174	-30.314	-26.111	-21.185	3.7996
100	509.59	515.76	521.64	5.4375	485.28	488.67	491.67	2.4562	-36.364	-27.088	-17.918	6.6454

Device Test: 19.42 RESET_SLEW_RATE_FALL(tsr_RESETB1_Falling/RESETB1/7/14/0/0/0/@RESET_SLEW_RATE_FALL)





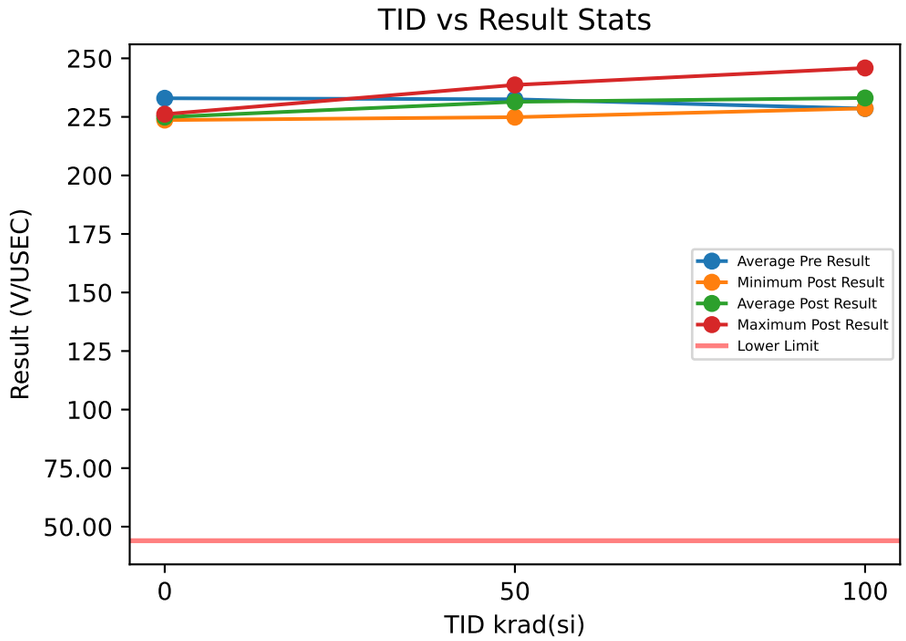
Test Results (Lower Limit = 44.0 (V/USEC))

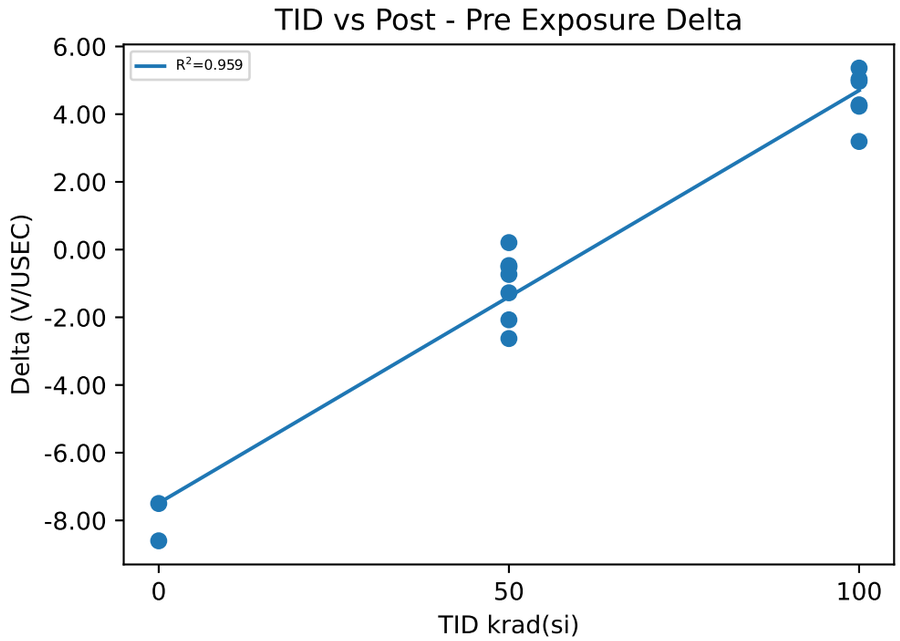
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	223.04	221.16	-1.879
89	50	Biased	223.03	223.66	0.631
90	50	Biased	220.65	220.92	0.273
92	50	Biased	222.32	221.08	-1.243
93	50	Unbiased	220.53	219.92	-0.613
94	50	Unbiased	220.4	219.85	-0.555
95	50	Unbiased	220.92	221.44	0.521
96	100	Biased	218.28	222.67	4.387
97	100	Biased	220.57	224.32	3.741
98	100	Biased	222.38	227.76	5.389
99	100	Unbiased	217.68	221.91	4.238
100	100	Unbiased	219.93	223.8	3.866
101	100	Unbiased	218.26	220.82	2.555
102	0	Correlation	222.81	217.31	-5.493
103	0	Correlation	222.77	217.68	-5.086

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	222.77	222.79	222.81	0.027577	217.31	217.5	217.68	0.26022	-5.493	-5.2895	-5.086	0.28779
50	220.4	221.56	223.04	1.1962	219.85	221.15	223.66	1.2694	-1.879	-0.40929	0.631	0.9426
100	217.68	219.52	222.38	1.7861	220.82	223.55	227.76	2.4217	2.555	4.0293	5.389	0.92775

Device Test: 19.43 RESET_SLEW_RATE_FALL(tsr_RESETB2_Falling/RESETB2/7/14/0/0/0/@RESET_SLEW_RATE_FALL)





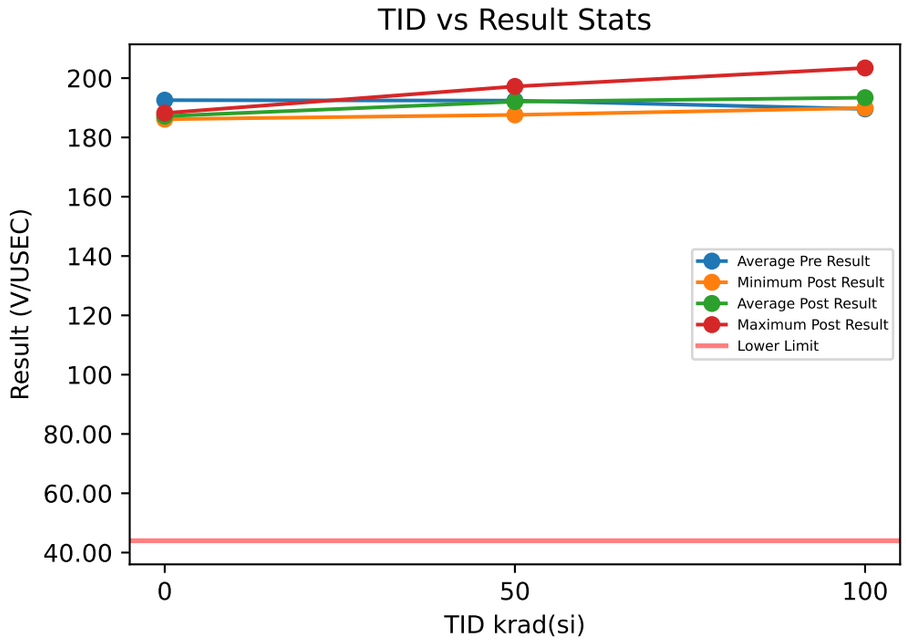
Test Results (Lower Limit = 44.0 (V/USEC))

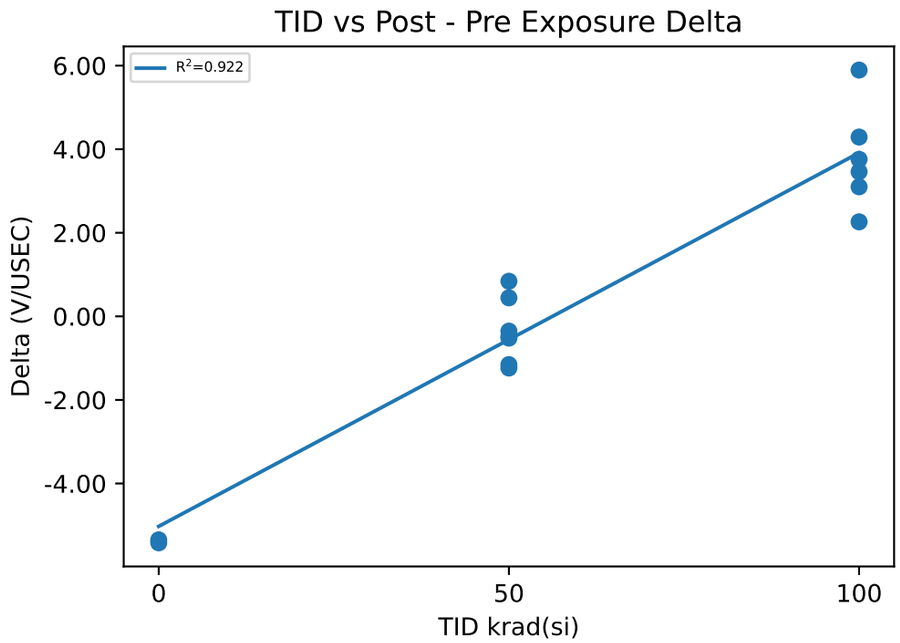
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	230.89	231.1	0.206
89	50	Biased	239.92	238.64	-1.276
90	50	Biased	233.57	230.94	-2.628
92	50	Biased	237.5	236.76	-0.734
93	50	Unbiased	225.34	224.87	-0.473
94	50	Unbiased	232.94	232.43	-0.516
95	50	Unbiased	227.42	225.35	-2.075
96	100	Biased	227.88	232.91	5.035
97	100	Biased	225.42	228.62	3.194
98	100	Biased	241.65	245.88	4.235
99	100	Unbiased	225.19	230.16	4.971
100	100	Unbiased	226.55	230.82	4.276
101	100	Unbiased	224.62	229.98	5.362
102	0	Correlation	231.13	223.63	-7.501
103	0	Correlation	234.75	226.15	-8.603

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	231.13	232.94	234.75	2.5618	223.63	224.89	226.15	1.7826	-8.603	-8.052	-7.501	0.77923
50	225.34	232.51	239.92	5.1797	224.87	231.44	238.64	5.194	-2.628	-1.0709	0.206	0.9903
100	224.62	228.55	241.65	6.5203	228.62	233.06	245.88	6.4357	3.194	4.5122	5.362	0.78438

Device Test: 19.44 RESET_SLEW_RATE_FALL(tsr_RESETB3_Falling/RESETB3/7/14/0/0/0/@RESET_SLEW_RATE_FALL)





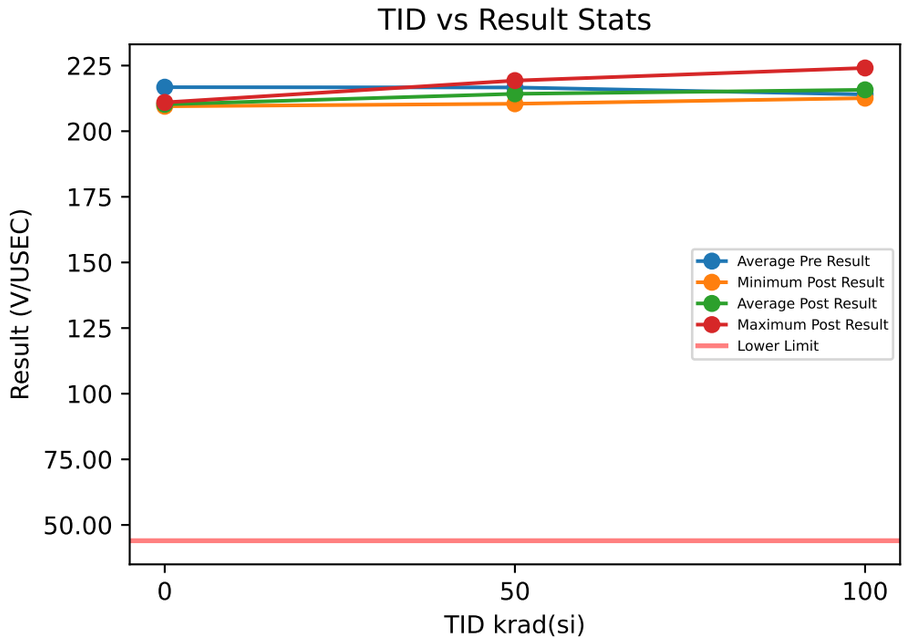
Test Results (Lower Limit = 44.0 (V/USEC))

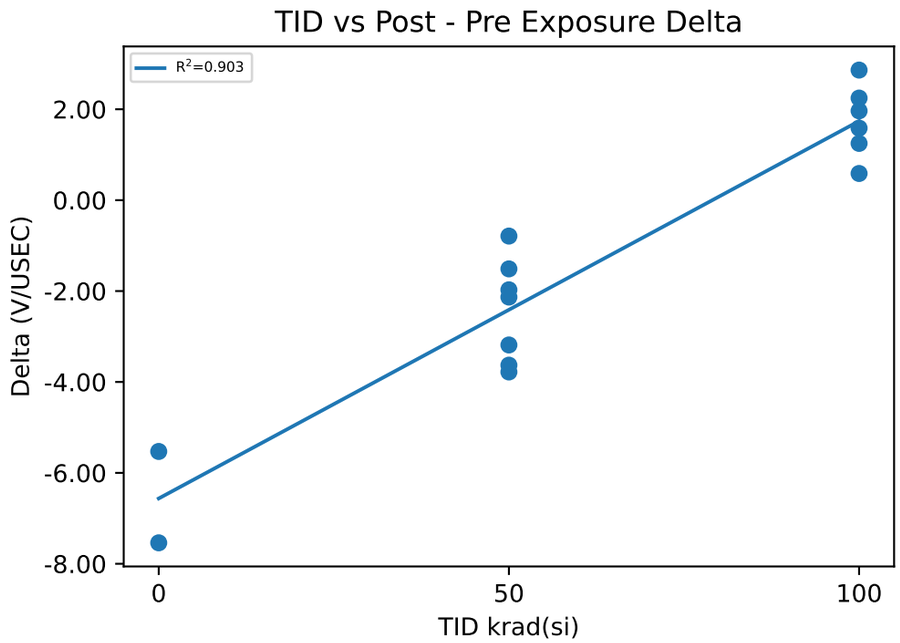
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	191.72	191.25	-0.475
89	50	Biased	196.75	197.2	0.443
90	50	Biased	192.93	191.69	-1.237
92	50	Biased	194.84	195.68	0.84
93	50	Unbiased	188.13	187.6	-0.521
94	50	Unbiased	193.77	193.42	-0.353
95	50	Unbiased	188.84	187.68	-1.155
96	100	Biased	190.86	193.96	3.1
97	100	Biased	187.06	190.53	3.461
98	100	Biased	197.53	203.43	5.894
99	100	Unbiased	186.78	190.54	3.758
100	100	Unbiased	187.8	192.09	4.291
101	100	Unbiased	187.66	189.92	2.262
102	0	Correlation	191.57	186.15	-5.42
103	0	Correlation	193.57	188.22	-5.349

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	191.57	192.57	193.57	1.4156	186.15	187.18	188.22	1.4658	-5.42	-5.3845	-5.349	0.050205
50	188.13	192.43	196.75	3.1232	187.6	192.08	197.2	3.6786	-1.237	-0.35114	0.84	0.76644
100	186.78	189.62	197.53	4.1436	189.92	193.41	203.43	5.1196	2.262	3.7943	5.894	1.2327

Device Test: 19.45 RESET_SLEW_RATE_FALL(tsr_RESETB4_Falling/RESETB4/7/14/0/0/0/@RESET_SLEW_RATE_FALL)





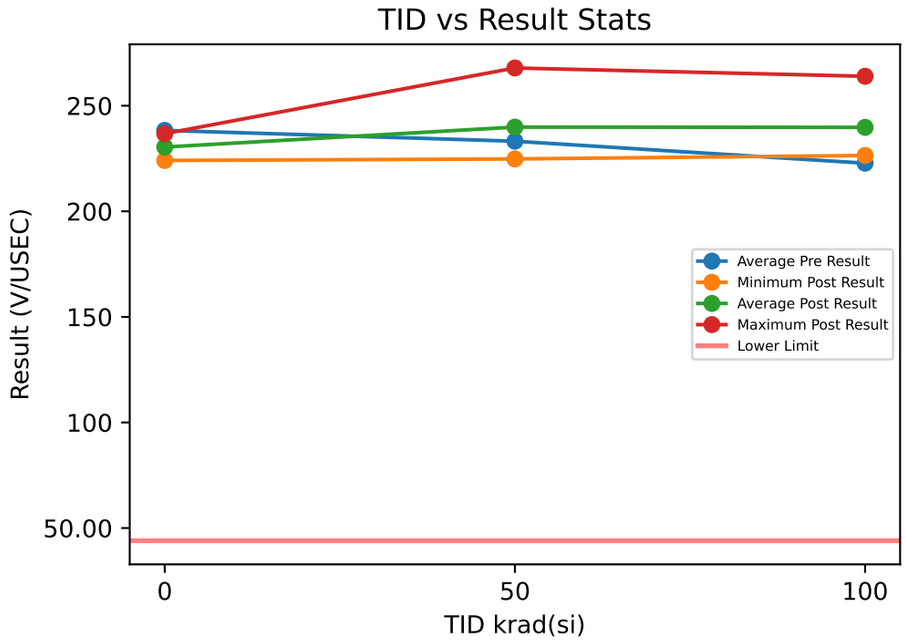
Test Results (Lower Limit = 44.0 (V/USEC))

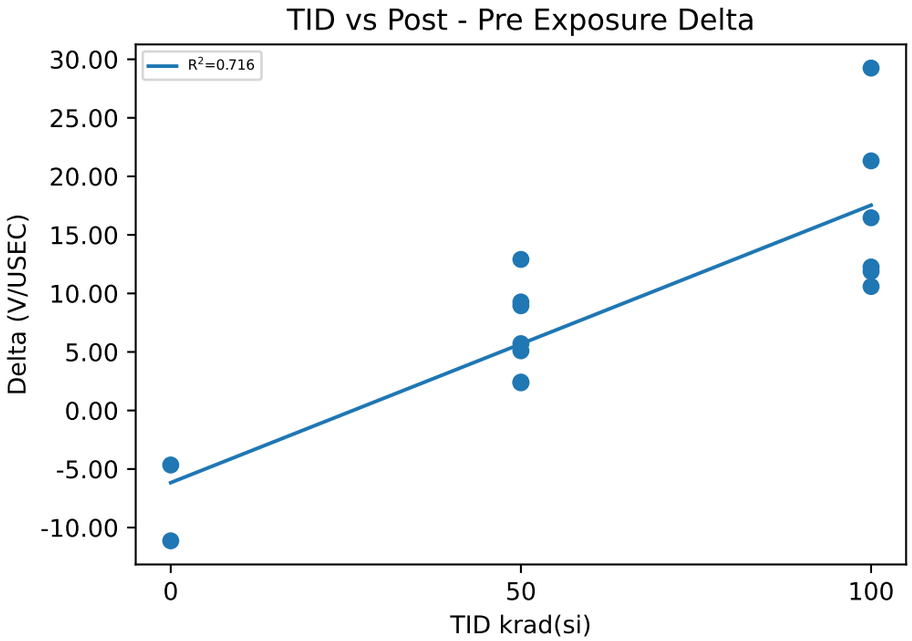
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	214.83	213.32	-1.512
89	50	Biased	221.41	219.28	-2.132
90	50	Biased	216.87	213.09	-3.78
92	50	Biased	219.62	215.99	-3.63
93	50	Unbiased	211.24	210.45	-0.79
94	50	Unbiased	219.82	216.63	-3.186
95	50	Unbiased	212.87	210.9	-1.972
96	100	Biased	215.44	216.03	0.587
97	100	Biased	210.9	213.14	2.246
98	100	Biased	222.84	224.09	1.249
99	100	Unbiased	210.01	212.88	2.862
100	100	Unbiased	213.91	215.87	1.965
101	100	Unbiased	210.99	212.58	1.585
102	0	Correlation	215.02	209.49	-5.529
103	0	Correlation	218.51	210.97	-7.539

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	215.02	216.76	218.51	2.4657	209.49	210.23	210.97	1.0444	-7.539	-6.534	-5.529	1.4213
50	211.24	216.67	221.41	3.8388	210.45	214.24	219.28	3.211	-3.78	-2.4289	-0.79	1.1303
100	210.01	214.02	222.84	4.7905	212.58	215.76	224.09	4.352	0.587	1.749	2.862	0.79493

Device Test: 19.46 PWRGD_SLEW_RATE_FALL(tsr_PWRGD_Falling/PWRGD/7/14/0/0/0/@PWRGD_SLEW_RATE_FALL)





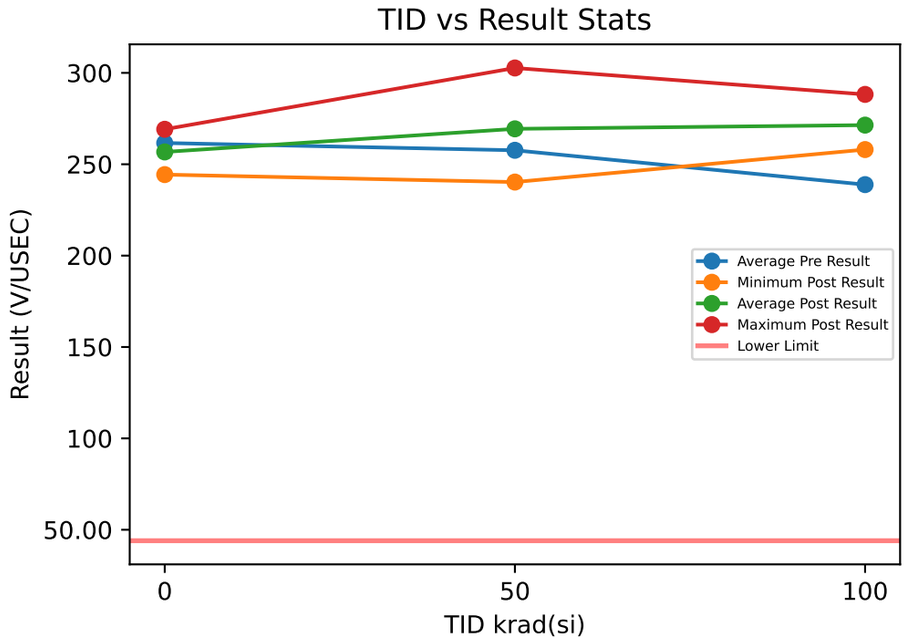
Test Results (Lower Limit = 44.0 (V/USEC))

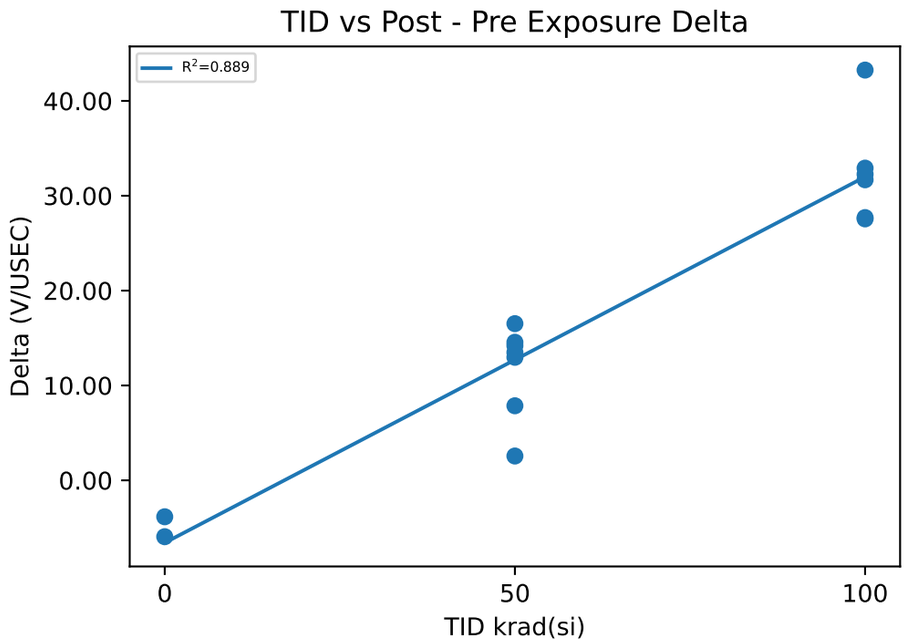
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	225.47	230.57	5.1
89	50	Biased	239.66	252.57	12.904
90	50	Biased	224.19	226.61	2.424
92	50	Biased	236.97	246.25	9.271
93	50	Unbiased	224.74	230.45	5.71
94	50	Unbiased	258.93	267.88	8.947
95	50	Unbiased	222.43	224.8	2.366
96	100	Biased	222.96	244.29	21.324
97	100	Biased	224.69	241.15	16.462
98	100	Biased	234.7	263.95	29.25
99	100	Unbiased	214.18	226.44	12.256
100	100	Unbiased	222.58	234.46	11.88
101	100	Unbiased	217.65	228.24	10.591
102	0	Correlation	228.74	224.08	-4.657
103	0	Correlation	247.91	236.78	-11.134

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	228.74	238.32	247.91	13.557	224.08	230.43	236.78	8.9767	-11.134	-7.8955	-4.657	4.5799
50	222.43	233.2	258.93	13.207	224.8	239.87	267.88	16.148	2.366	6.6746	12.904	3.8891
100	214.18	222.79	234.7	7.0138	226.44	239.75	263.95	13.753	10.591	16.961	29.25	7.1949

Device Test: 19.47 WDO_SLEW_RATE_FALL(tsr_WDOB_Falling/WDOB/7/14/0/0/0/@WDO_SLEW_RATE_FALL)





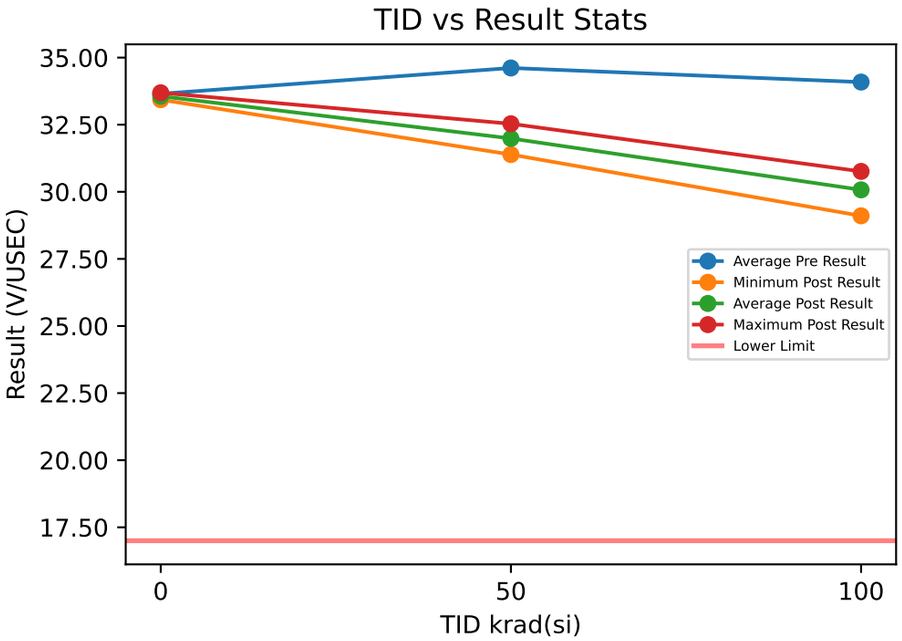
Test Results (Lower Limit = 44.0 (V/USEC))

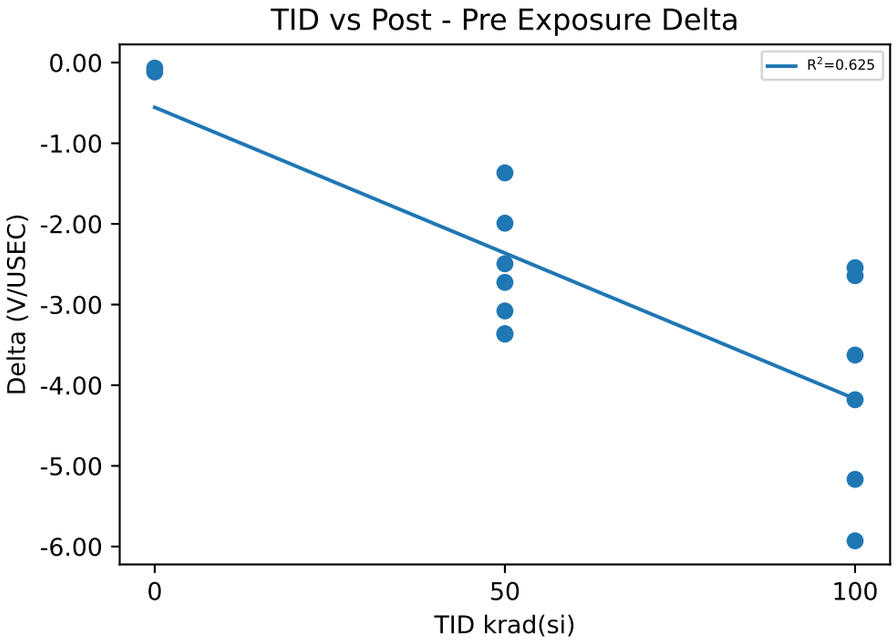
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	245.47	260.03	14.555
89	50	Biased	275.5	288.98	13.482
90	50	Biased	244.07	258.26	14.194
92	50	Biased	258.61	271.58	12.971
93	50	Unbiased	247.35	263.87	16.517
94	50	Unbiased	300.12	302.68	2.563
95	50	Unbiased	232.39	240.25	7.86
96	100	Biased	239.59	282.84	43.25
97	100	Biased	248	275.69	27.698
98	100	Biased	256.54	288.22	31.685
99	100	Unbiased	225.45	258.37	32.912
100	100	Unbiased	233.07	265.34	32.263
101	100	Unbiased	230.47	258.04	27.562
102	0	Correlation	250.28	244.34	-5.943
103	0	Correlation	272.98	269.14	-3.842

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	250.28	261.63	272.98	16.049	244.34	256.74	269.14	17.535	-5.943	-4.8925	-3.842	1.4856
50	232.39	257.65	300.12	23.093	240.25	269.38	302.68	20.768	2.563	11.735	16.517	4.8406
100	225.45	238.85	256.54	11.662	258.04	271.42	288.22	12.788	27.562	32.562	43.25	5.7249

Device Test: 19.5 WDO_SLEW_RATE_RISE(tsr_WDOB_Rising/WDOB/1.6/3/0/0/0/@WDO_SLEW_RATE_RISE)





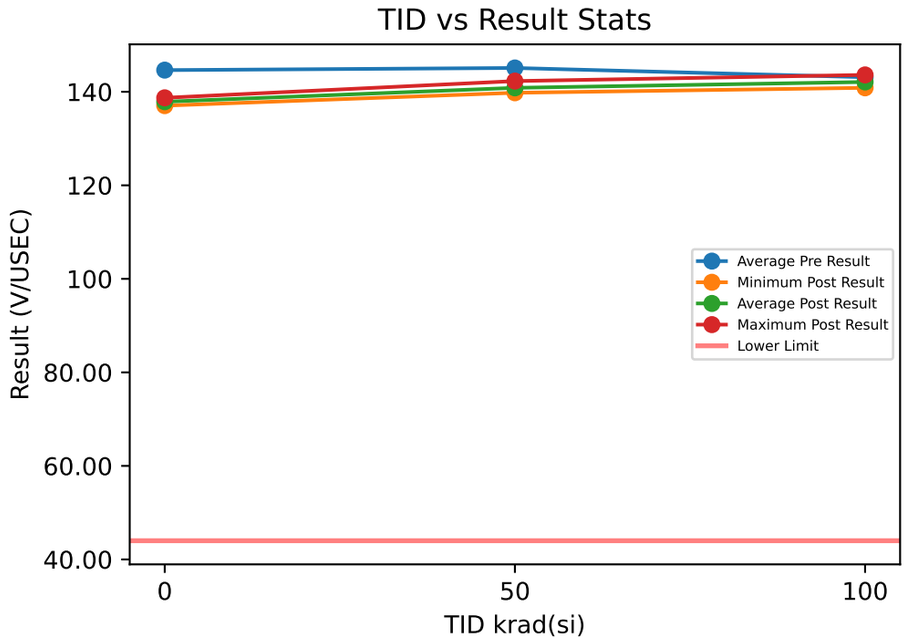
Test Results (Lower Limit = 17.0 (V/USEC))

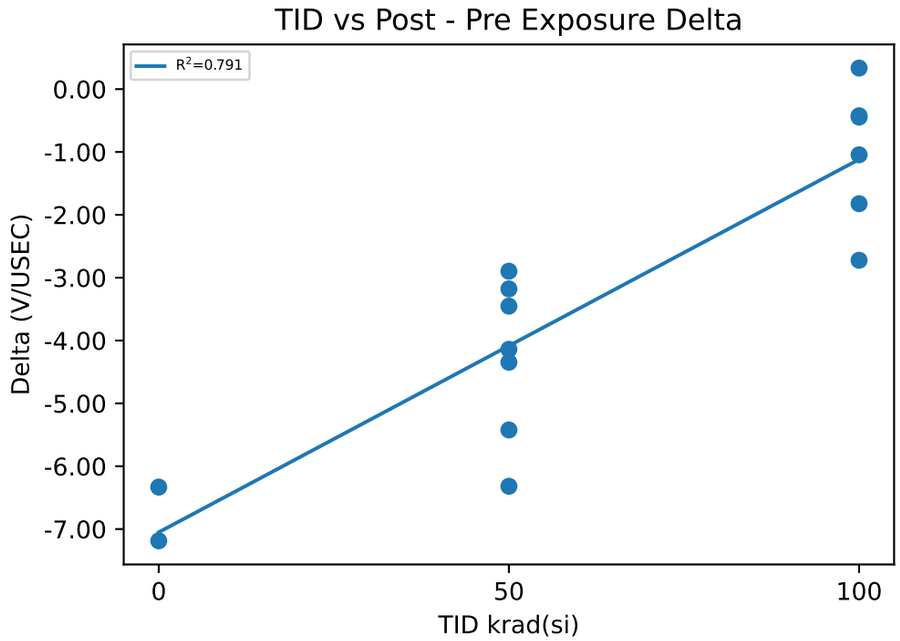
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	34.776	32.051	-2.725
89	50	Biased	35.896	32.535	-3.361
90	50	Biased	35.144	31.778	-3.366
92	50	Biased	33.38	31.389	-1.991
93	50	Unbiased	33.304	31.937	-1.367
94	50	Unbiased	34.635	32.141	-2.494
95	50	Unbiased	35.16	32.081	-3.079
96	100	Biased	34.55	30.37	-4.18
97	100	Biased	33.176	29.55	-3.626
98	100	Biased	35.034	29.105	-5.929
99	100	Unbiased	35.184	30.017	-5.167
100	100	Unbiased	33.402	30.76	-2.642
101	100	Unbiased	33.182	30.639	-2.543
102	0	Correlation	33.758	33.69	-0.068
103	0	Correlation	33.547	33.431	-0.116

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	33.547	33.653	33.758	0.1492	33.431	33.56	33.69	0.18314	-0.116	-0.092	-0.068	0.033941
50	33.304	34.614	35.896	0.95639	31.389	31.987	32.535	0.35136	-3.366	-2.6261	-1.367	0.74258
100	33.176	34.088	35.184	0.94157	29.105	30.073	30.76	0.64718	-5.929	-4.0145	-2.543	1.358

Device Test: 19.6 RESET_SLEW_RATE_FALL(tsr_RESETB1_Falling/RESETB1/1.6/3/0/0/0/@RESET_SLEW_RATE_FALL)





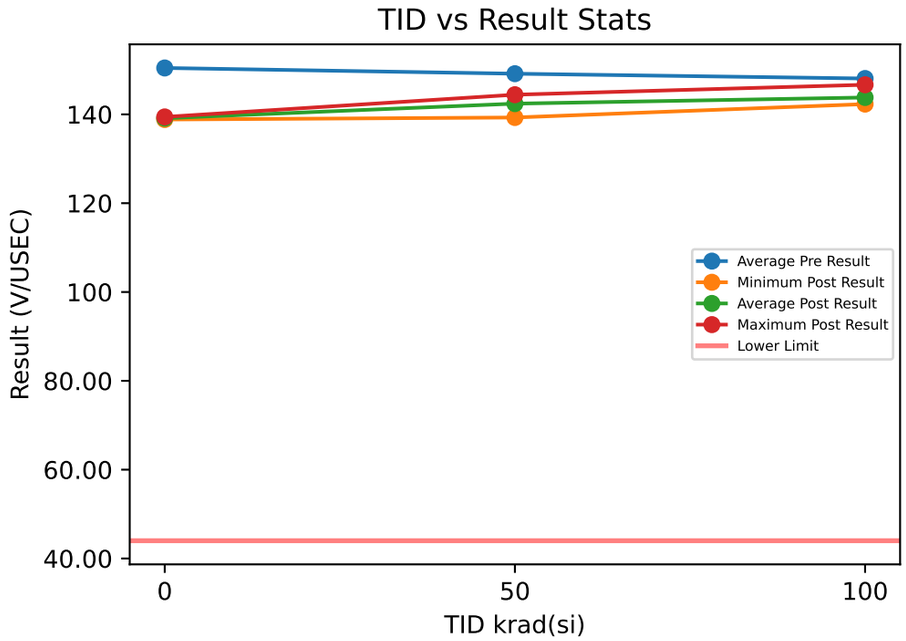
Test Results (Lower Limit = 44.0 (V/USEC))

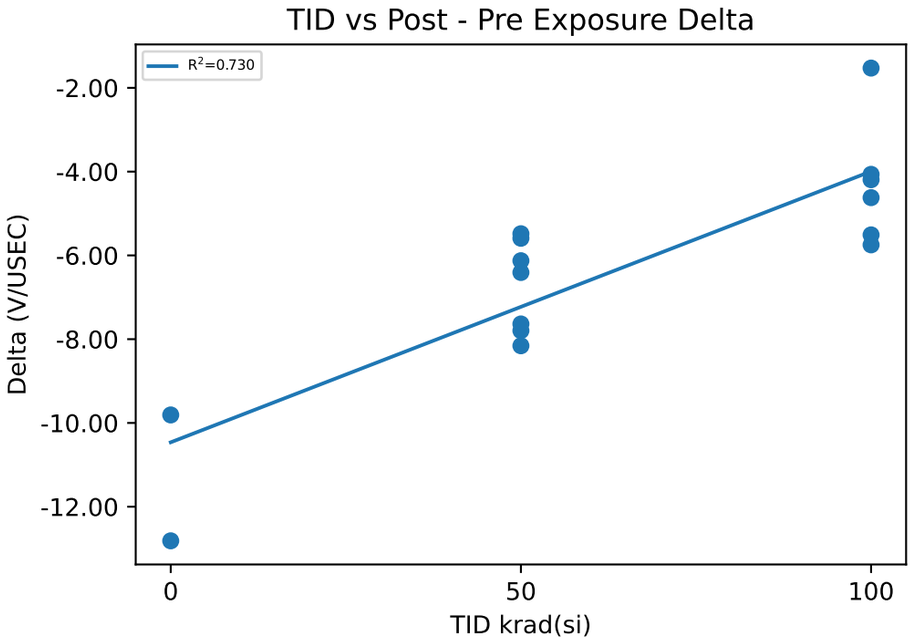
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	146.46	141.04	-5.423
89	50	Biased	145.74	142.29	-3.453
90	50	Biased	144.76	140.62	-4.14
92	50	Biased	146.97	140.66	-6.319
93	50	Unbiased	142.68	139.79	-2.897
94	50	Unbiased	145.08	140.74	-4.346
95	50	Unbiased	143.94	140.77	-3.179
96	100	Biased	142.11	141.07	-1.045
97	100	Biased	143.28	143.61	0.335
98	100	Biased	143.84	143.39	-0.445
99	100	Unbiased	142.67	140.85	-1.823
100	100	Unbiased	145.53	142.81	-2.723
101	100	Unbiased	141.29	140.86	-0.424
102	0	Correlation	143.37	137.04	-6.332
103	0	Correlation	145.9	138.71	-7.187

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	143.37	144.63	145.9	1.7876	137.04	137.87	138.71	1.183	-7.187	-6.7595	-6.332	0.60458
50	142.68	145.09	146.97	1.4756	139.79	140.84	142.29	0.74751	-6.319	-4.251	-2.897	1.2444
100	141.29	143.12	145.53	1.4791	140.85	142.1	143.61	1.3129	-2.723	-1.0208	0.335	1.1016

Device Test: 19.7 RESET_SLEW_RATE_FALL(tsr_RESETB2_Falling/RESETB2/1.6/3/0/0/0/@RESET_SLEW_RATE_FALL)





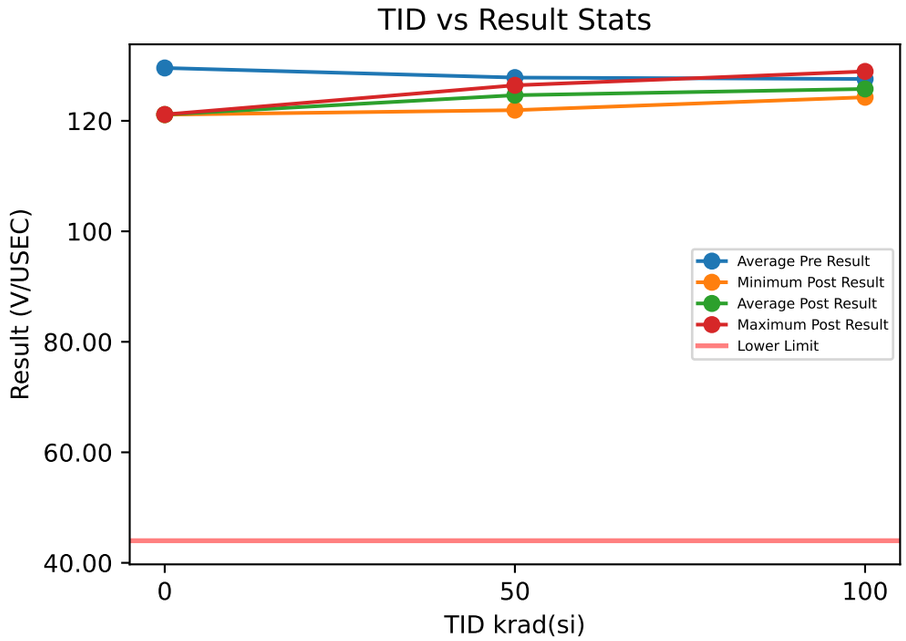
Test Results (Lower Limit = 44.0 (V/USEC))

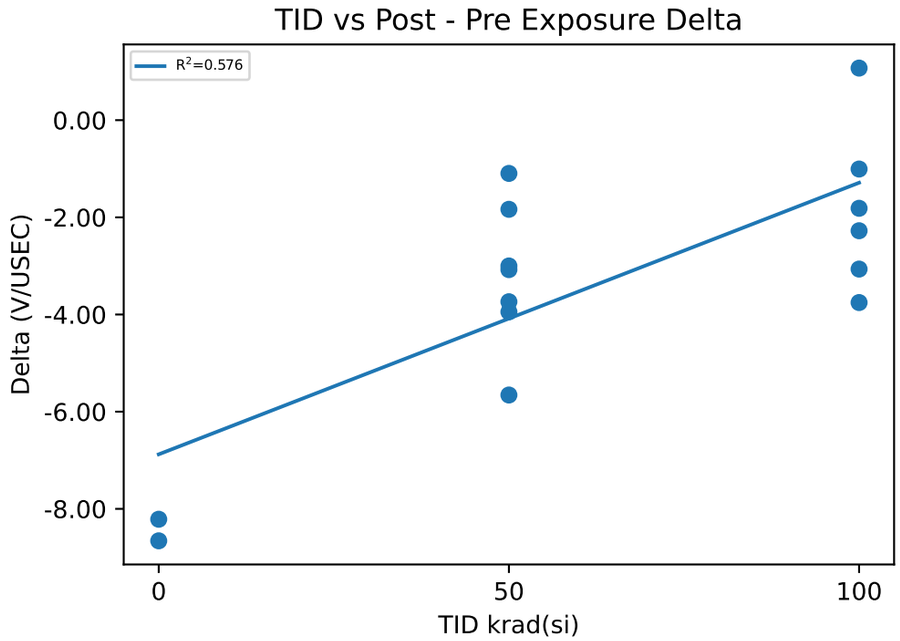
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	151.15	143.51	-7.637
89	50	Biased	150.55	144.43	-6.127
90	50	Biased	151.27	143.12	-8.157
92	50	Biased	149.94	143.54	-6.408
93	50	Unbiased	144.77	139.29	-5.483
94	50	Unbiased	150.21	142.41	-7.796
95	50	Unbiased	146.19	140.6	-5.591
96	100	Biased	151.19	145.44	-5.748
97	100	Biased	144.17	142.65	-1.528
98	100	Biased	151.28	146.66	-4.621
99	100	Unbiased	146.96	142.76	-4.193
100	100	Unbiased	147.82	142.31	-5.51
101	100	Unbiased	147.02	142.95	-4.065
102	0	Correlation	151.66	138.84	-12.814
103	0	Correlation	149.23	139.43	-9.809

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	149.23	150.44	151.66	1.7126	138.84	139.13	139.43	0.41224	-12.814	-11.311	-9.809	2.1249
50	144.77	149.16	151.27	2.5862	139.29	142.41	144.43	1.8281	-8.157	-6.7427	-5.483	1.1041
100	144.17	148.07	151.28	2.7441	142.31	143.8	146.66	1.802	-5.748	-4.2775	-1.528	1.5107

Device Test: 19.8 RESET_SLEW_RATE_FALL(tsr_RESETB3_Falling/RESETB3/1.6/3/0/0/0/@RESET_SLEW_RATE_FALL)





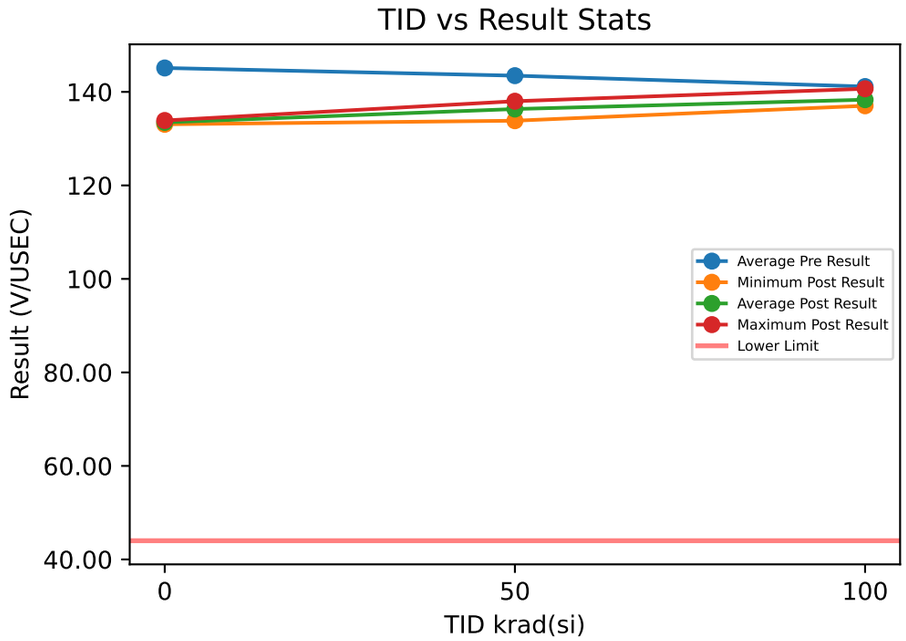
Test Results (Lower Limit = 44.0 (V/USEC))

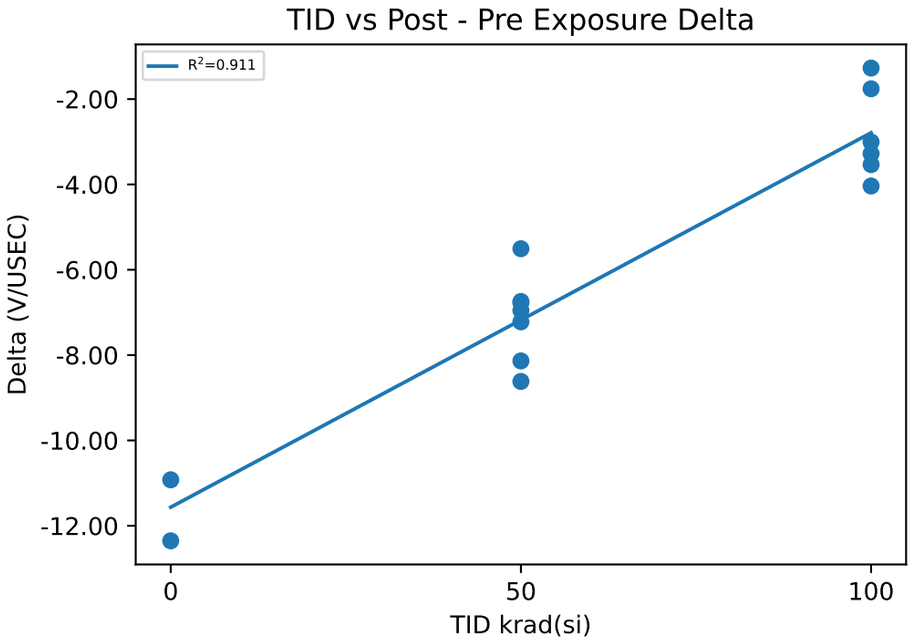
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	127.33	125.5	-1.835
89	50	Biased	129.43	126.43	-3.001
90	50	Biased	128.65	125.58	-3.076
92	50	Biased	127.07	125.97	-1.096
93	50	Unbiased	125.67	121.93	-3.737
94	50	Unbiased	128.64	124.69	-3.945
95	50	Unbiased	128	122.34	-5.657
96	100	Biased	129.52	126.45	-3.065
97	100	Biased	124.74	125.81	1.072
98	100	Biased	130.75	128.94	-1.814
99	100	Unbiased	126.86	124.58	-2.276
100	100	Unbiased	125.27	124.26	-1.006
101	100	Unbiased	128.3	124.54	-3.754
102	0	Correlation	129.36	121.14	-8.214
103	0	Correlation	129.77	121.11	-8.658

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	129.36	129.56	129.77	0.29062	121.11	121.13	121.14	0.023335	-8.658	-8.436	-8.214	0.31396
50	125.67	127.83	129.43	1.2533	121.93	124.63	126.43	1.7884	-5.657	-3.1924	-1.096	1.4846
100	124.74	127.57	130.75	2.3768	124.26	125.77	128.94	1.7719	-3.754	-1.8072	1.072	1.7043

Device Test: 19.9 RESET_SLEW_RATE_FALL(tsr_RESETB4_Falling/RESETB4/1.6/3/0/0/0/@RESET_SLEW_RATE_FALL)





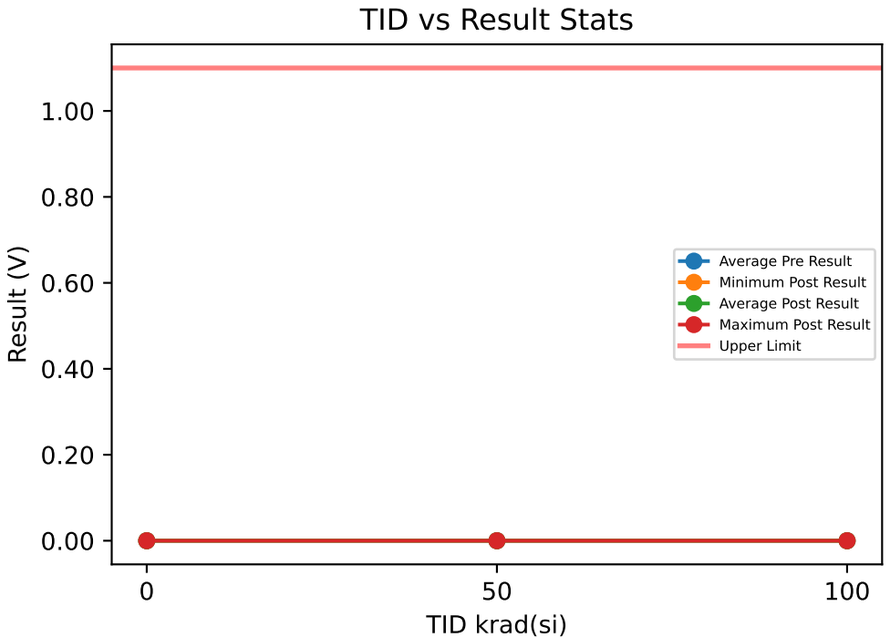
Test Results (Lower Limit = 44.0 (V/USEC))

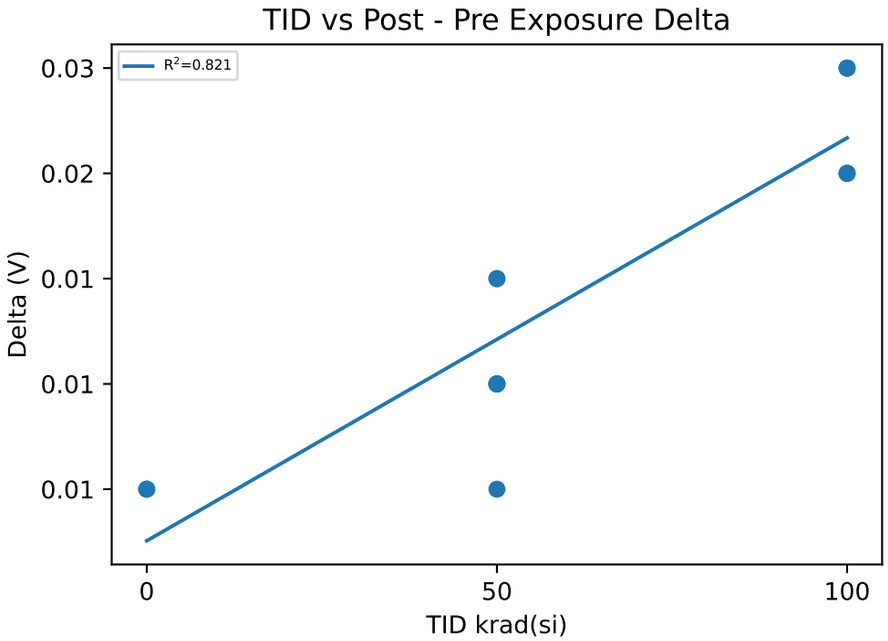
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	142.63	135.88	-6.744
89	50	Biased	145.91	137.78	-8.137
90	50	Biased	142.86	137.35	-5.507
92	50	Biased	143.44	136.48	-6.953
93	50	Unbiased	141.06	133.84	-7.22
94	50	Unbiased	144.78	138.01	-6.771
95	50	Unbiased	143.63	135.01	-8.618
96	100	Biased	142.53	139	-3.536
97	100	Biased	140.31	137.03	-3.277
98	100	Biased	143.67	140.67	-3.005
99	100	Unbiased	138.84	137.09	-1.759
100	100	Unbiased	139.36	138.09	-1.273
101	100	Unbiased	142.14	138.1	-4.037
102	0	Correlation	144	133.07	-10.923
103	0	Correlation	146.24	133.88	-12.353

Test Statistics (V/USEC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	144	145.12	146.24	1.586	133.07	133.48	133.88	0.57488	-12.353	-11.638	-10.923	1.0112
50	141.06	143.47	145.91	1.5611	133.84	136.34	138.01	1.535	-8.618	-7.1357	-5.507	1.0148
100	138.84	141.14	143.67	1.923	137.03	138.33	140.67	1.3614	-4.037	-2.8145	-1.273	1.0729

Device Test: 25.1 SR_UVLO_HT(T_MIN_SR/SR_UVLOB/3.3/3/0/0/0/@SR_UVLO_HT)





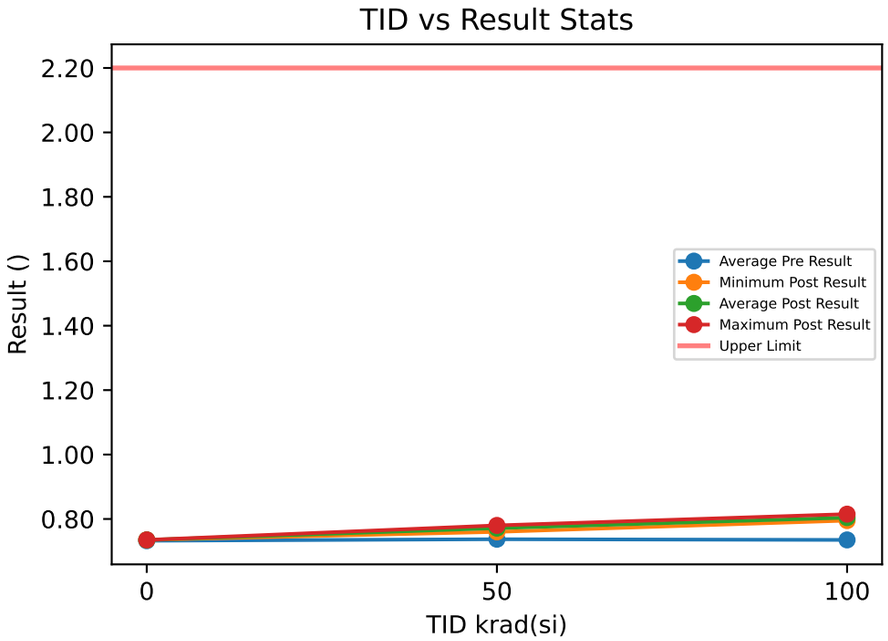
Test Results (Upper Limit = 1.1 (V))

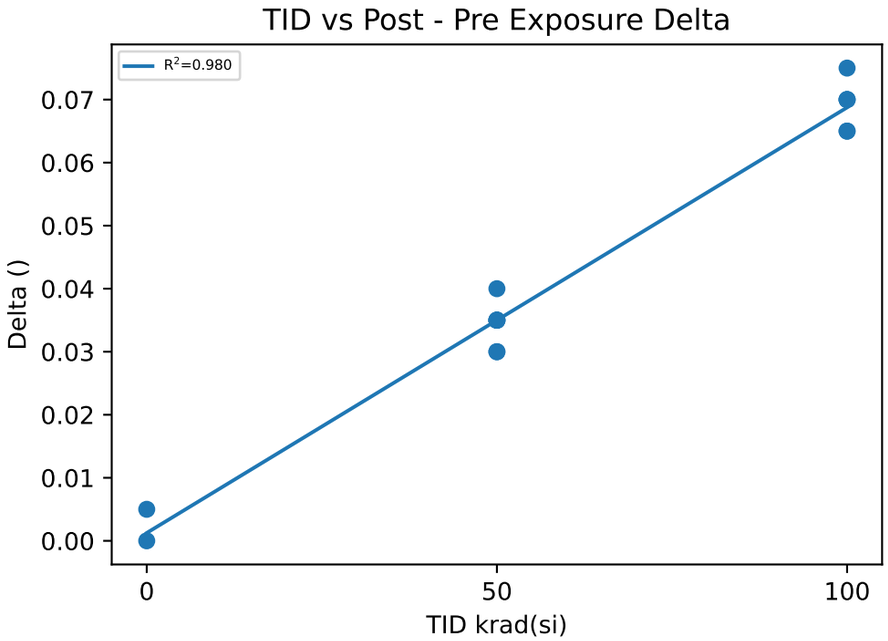
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	6.4e-07	6.5e-07	0.01
89	50	Biased	6.35e-07	6.45e-07	0.01
90	50	Biased	6.45e-07	6.5e-07	0.005
92	50	Biased	6.4e-07	6.5e-07	0.01
93	50	Unbiased	6.45e-07	6.55e-07	0.01
94	50	Unbiased	6.4e-07	6.55e-07	0.015
95	50	Unbiased	6.35e-07	6.5e-07	0.015
96	100	Biased	6.4e-07	6.6e-07	0.02
97	100	Biased	6.4e-07	6.6e-07	0.02
98	100	Biased	6.35e-07	6.55e-07	0.02
99	100	Unbiased	6.45e-07	6.7e-07	0.025
100	100	Unbiased	6.35e-07	6.6e-07	0.025
101	100	Unbiased	6.4e-07	6.65e-07	0.025
102	0	Correlation	6.4e-07	6.45e-07	0.005
103	0	Correlation	6.25e-07	6.3e-07	0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.25e-07	6.325e-07	6.4e-07	1.0607e-08	6.3e-07	6.375e-07	6.45e-07	1.0607e-08	0.005	0.005	0.005	0
50	6.35e-07	6.4e-07	6.45e-07	4.0825e-09	6.45e-07	6.5071e-07	6.55e-07	3.4503e-09	0.005	0.010714	0.015	0.0034503
100	6.35e-07	6.3917e-07	6.45e-07	3.7639e-09	6.55e-07	6.6167e-07	6.7e-07	5.164e-09	0.02	0.0225	0.025	0.0027386

Device Test: 25.10 SENSE_F_HT_PP(T_MIN_SENSE/SENSE4/3.3/14/0/0/0/@SENSE_F_HT_PP)





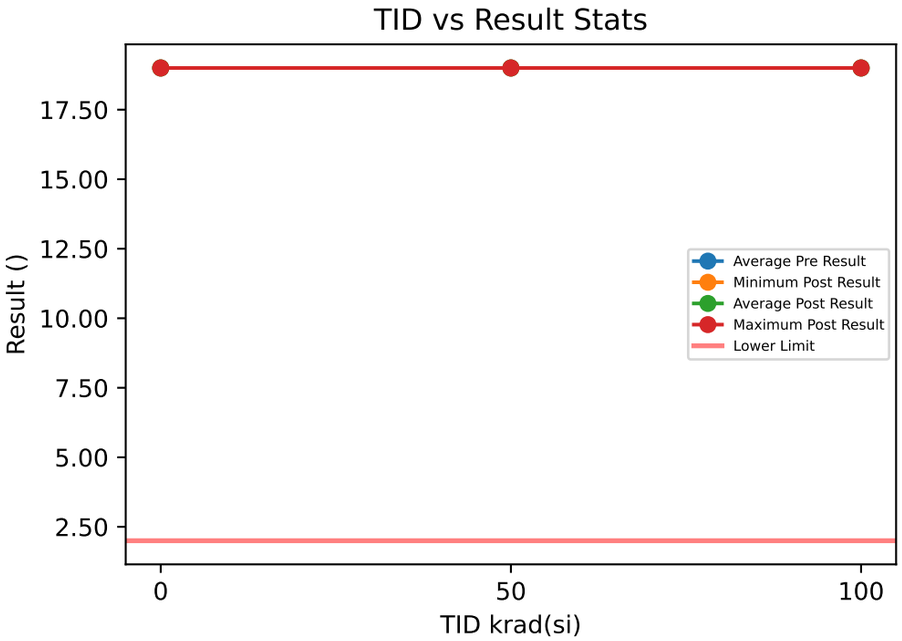
Test Results (Upper Limit = 2.2 ())

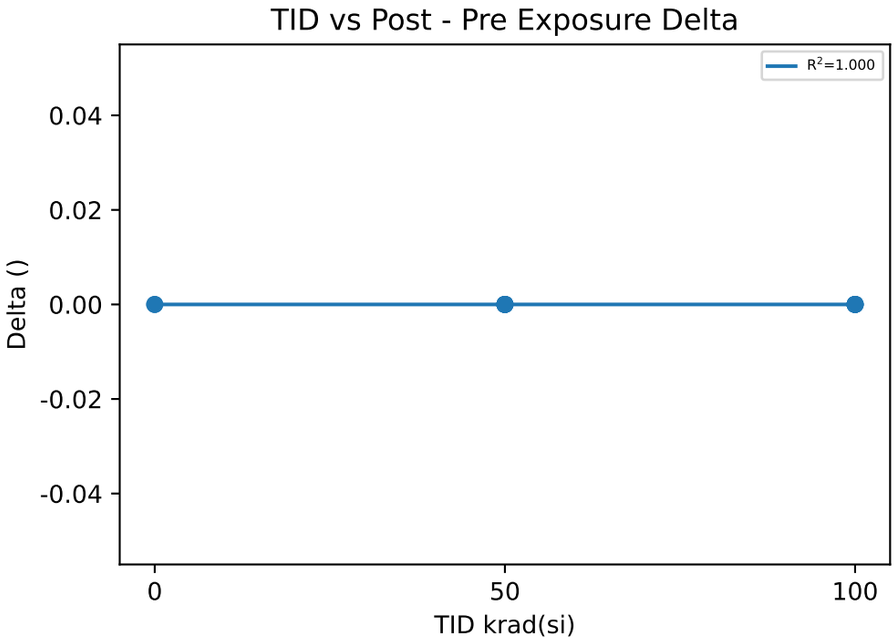
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.745	0.78	0.035
89	50	Biased	0.735	0.77	0.035
90	50	Biased	0.735	0.77	0.035
92	50	Biased	0.74	0.775	0.035
93	50	Unbiased	0.735	0.775	0.04
94	50	Unbiased	0.73	0.76	0.03
95	50	Unbiased	0.74	0.77	0.03
96	100	Biased	0.725	0.795	0.07
97	100	Biased	0.74	0.815	0.075
98	100	Biased	0.73	0.8	0.07
99	100	Unbiased	0.735	0.805	0.07
100	100	Unbiased	0.745	0.81	0.065
101	100	Unbiased	0.735	0.8	0.065
102	0	Correlation	0.735	0.735	0
103	0	Correlation	0.73	0.735	0.005

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.73	0.7325	0.735	0.0035355	0.735	0.735	0.735	0	0	0.0025	0.005	0.0035355
50	0.73	0.73714	0.745	0.0048795	0.76	0.77143	0.78	0.0062678	0.03	0.034286	0.04	0.0034503
100	0.725	0.735	0.745	0.0070711	0.795	0.80417	0.815	0.0073598	0.065	0.069167	0.075	0.0037639

Device Test: 25.11 WDI_HT(T_MIN_R1_WDI/WDI/3.3/3/0/0/0/@WDI_HT)





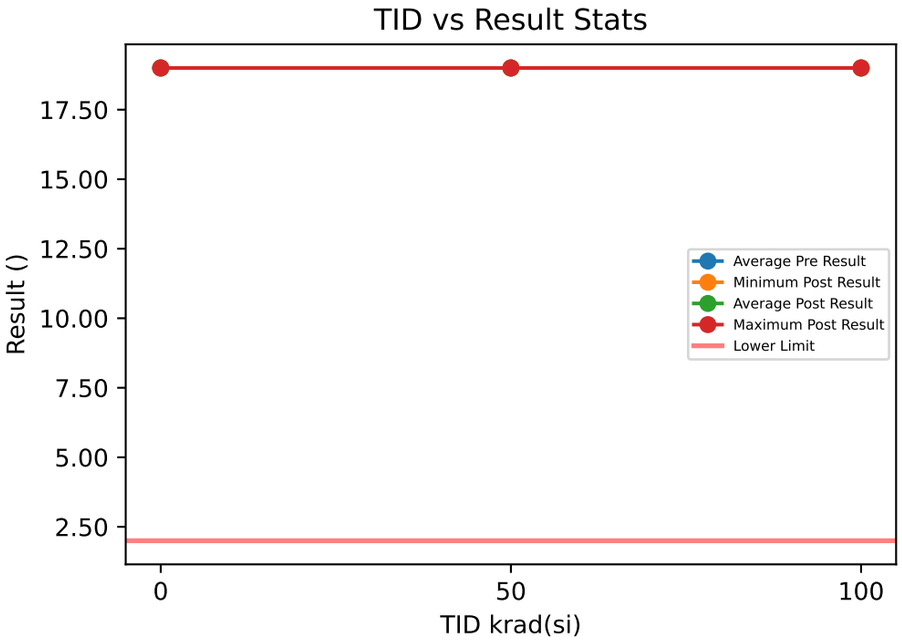
Test Results (Lower Limit = 2.0 ())

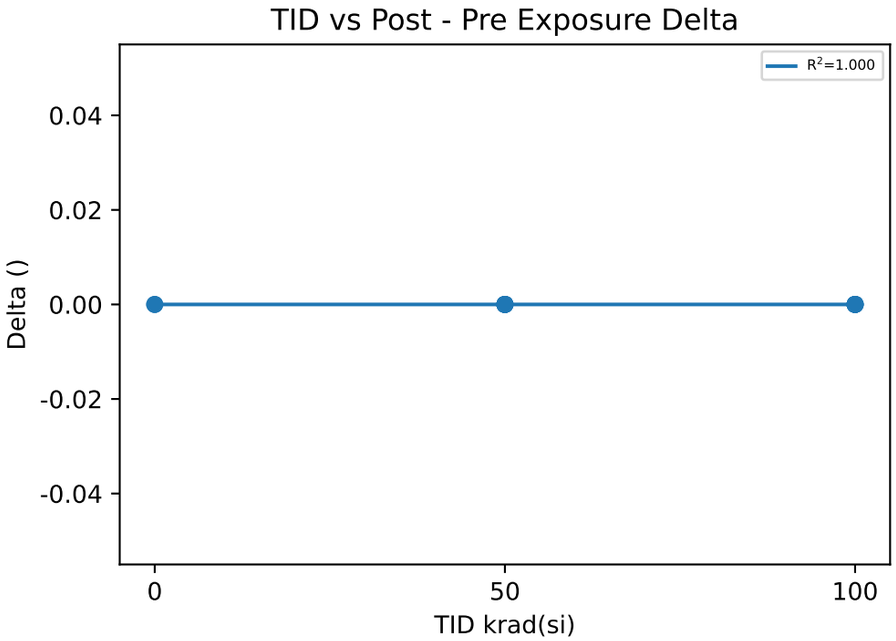
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19	19	0
89	50	Biased	19	19	0
90	50	Biased	19	19	0
92	50	Biased	19	19	0
93	50	Unbiased	19	19	0
94	50	Unbiased	19	19	0
95	50	Unbiased	19	19	0
96	100	Biased	19	19	0
97	100	Biased	19	19	0
98	100	Biased	19	19	0
99	100	Unbiased	19	19	0
100	100	Unbiased	19	19	0
101	100	Unbiased	19	19	0
102	0	Correlation	19	19	0
103	0	Correlation	19	19	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19	19	19	0	19	19	19	0	0	0	0	0
50	19	19	19	0	19	19	19	0	0	0	0	0
100	19	19	19	0	19	19	19	0	0	0	0	0

Device Test: 25.12 WDI_HT(T_MIN_R1_WDI/WDI/3.3/14/0/0/0/@WDI_HT)





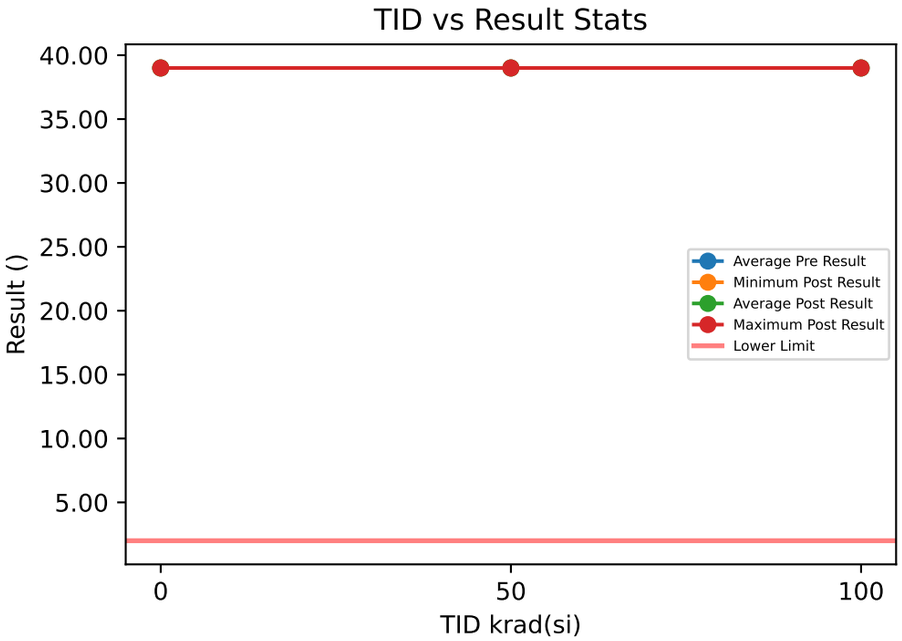
Test Results (Lower Limit = 2.0 ())

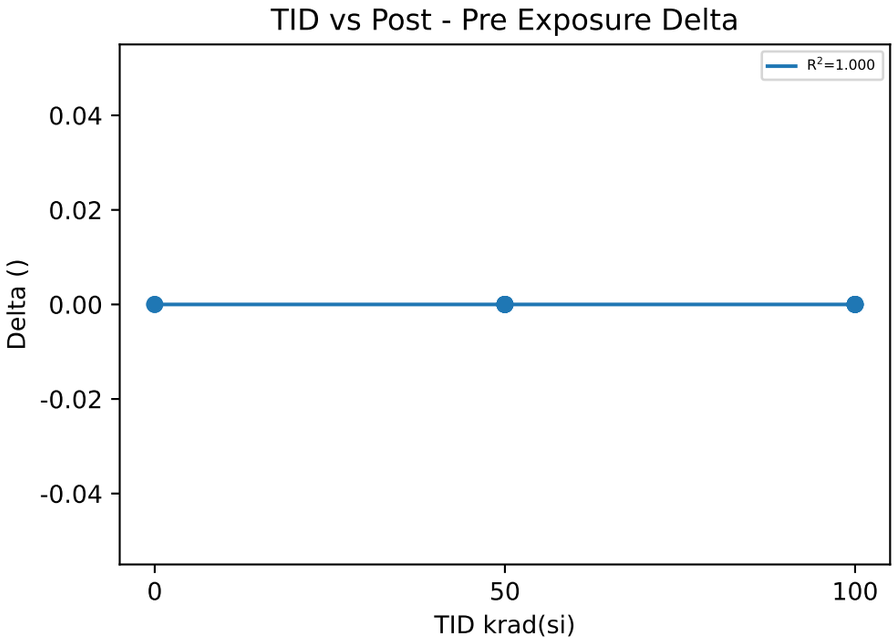
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	19	19	0
89	50	Biased	19	19	0
90	50	Biased	19	19	0
92	50	Biased	19	19	0
93	50	Unbiased	19	19	0
94	50	Unbiased	19	19	0
95	50	Unbiased	19	19	0
96	100	Biased	19	19	0
97	100	Biased	19	19	0
98	100	Biased	19	19	0
99	100	Unbiased	19	19	0
100	100	Unbiased	19	19	0
101	100	Unbiased	19	19	0
102	0	Correlation	19	19	0
103	0	Correlation	19	19	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19	19	19	0	19	19	19	0	0	0	0	0
50	19	19	19	0	19	19	19	0	0	0	0	0
100	19	19	19	0	19	19	19	0	0	0	0	0

Device Test: 25.13 WDI_HT(T_MIN_R2_WDI/WDI/3.3/3/0/0/0/@WDI_HT)





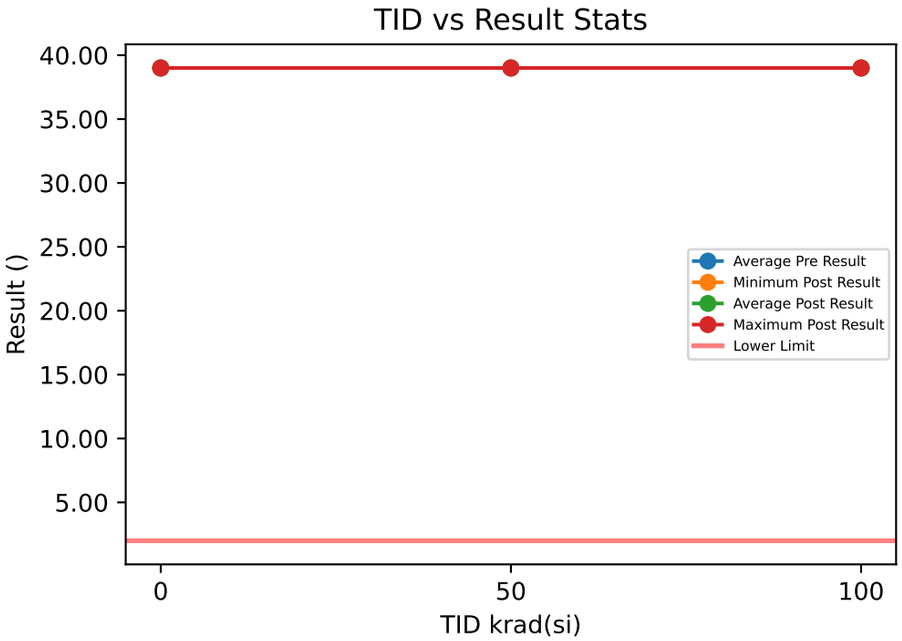
Test Results (Lower Limit = 2.0 ())

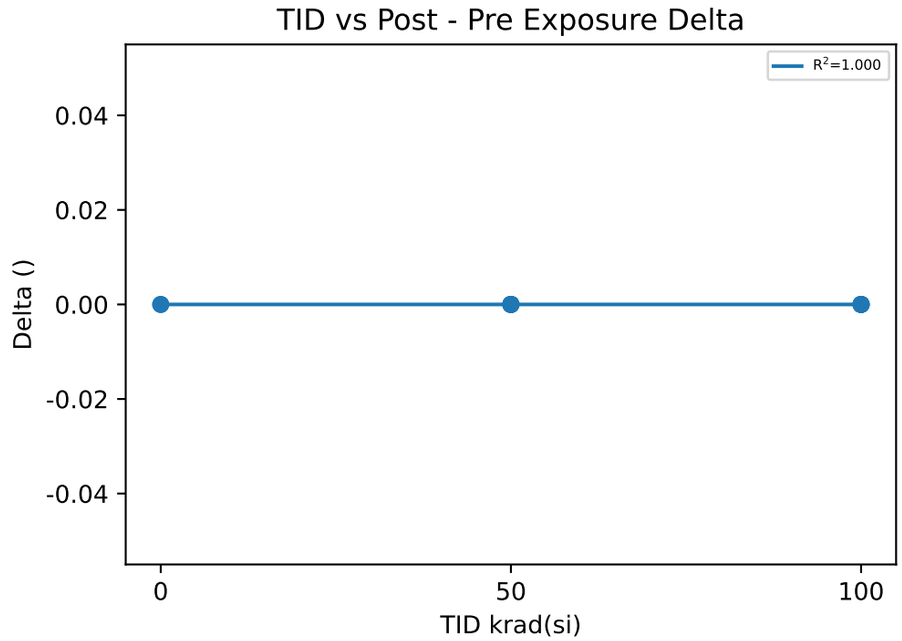
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	39	39	0
89	50	Biased	39	39	0
90	50	Biased	39	39	0
92	50	Biased	39	39	0
93	50	Unbiased	39	39	0
94	50	Unbiased	39	39	0
95	50	Unbiased	39	39	0
96	100	Biased	39	39	0
97	100	Biased	39	39	0
98	100	Biased	39	39	0
99	100	Unbiased	39	39	0
100	100	Unbiased	39	39	0
101	100	Unbiased	39	39	0
102	0	Correlation	39	39	0
103	0	Correlation	39	39	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	39	39	39	0	39	39	39	0	0	0	0	0
50	39	39	39	0	39	39	39	0	0	0	0	0
100	39	39	39	0	39	39	39	0	0	0	0	0

Device Test: 25.14 WDI_HT(T_MIN_R2_WDI/WDI/3.3/14/0/0/0/@WDI_HT)





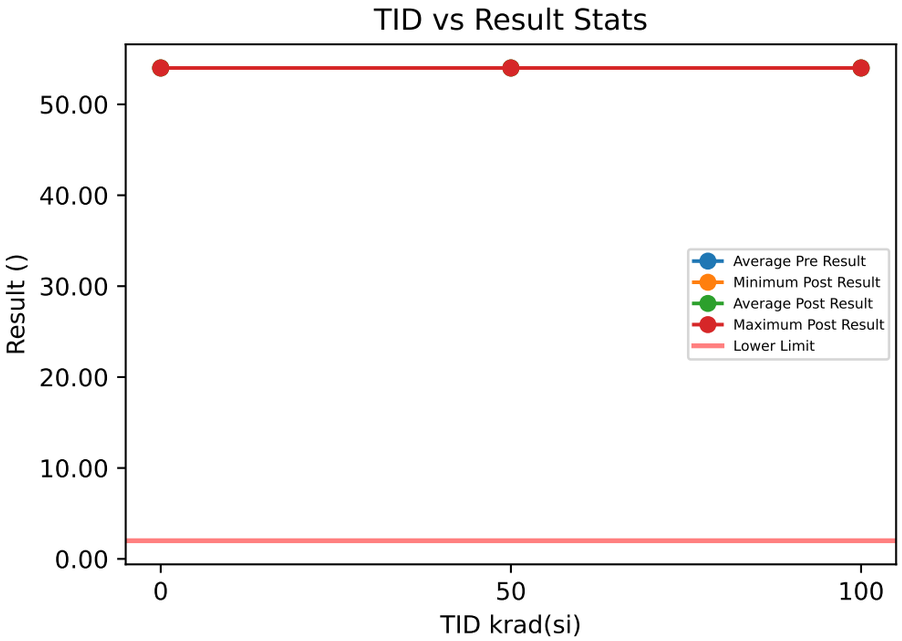
Test Results (Lower Limit = 2.0 ())

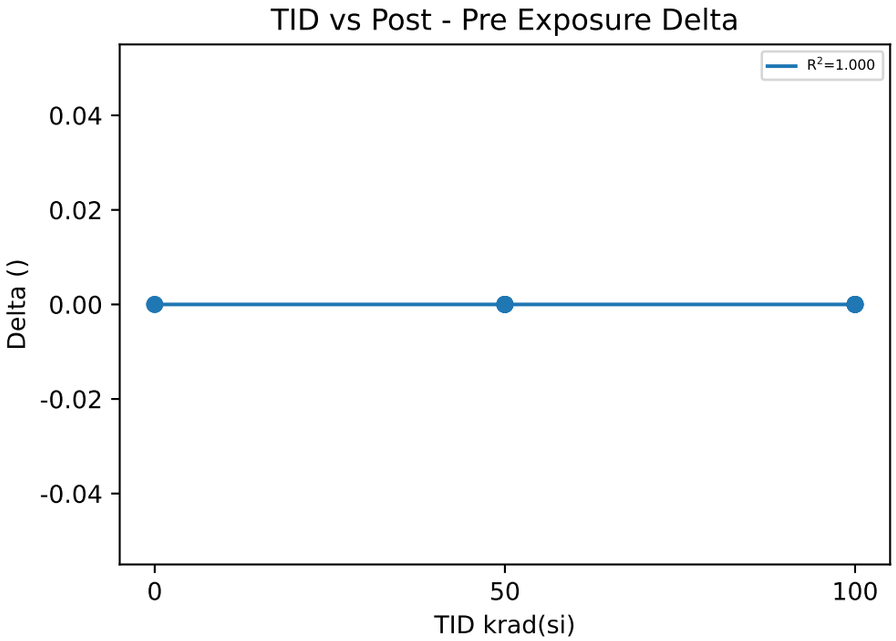
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	39	39	0
89	50	Biased	39	39	0
90	50	Biased	39	39	0
92	50	Biased	39	39	0
93	50	Unbiased	39	39	0
94	50	Unbiased	39	39	0
95	50	Unbiased	39	39	0
96	100	Biased	39	39	0
97	100	Biased	39	39	0
98	100	Biased	39	39	0
99	100	Unbiased	39	39	0
100	100	Unbiased	39	39	0
101	100	Unbiased	39	39	0
102	0	Correlation	39	39	0
103	0	Correlation	39	39	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	39	39	39	0	39	39	39	0	0	0	0	0
50	39	39	39	0	39	39	39	0	0	0	0	0
100	39	39	39	0	39	39	39	0	0	0	0	0

Device Test: 25.15 WDI_HT(T_MIN_R3_WDI/WDI/3.3/3/0/0/0/@WDI_HT)





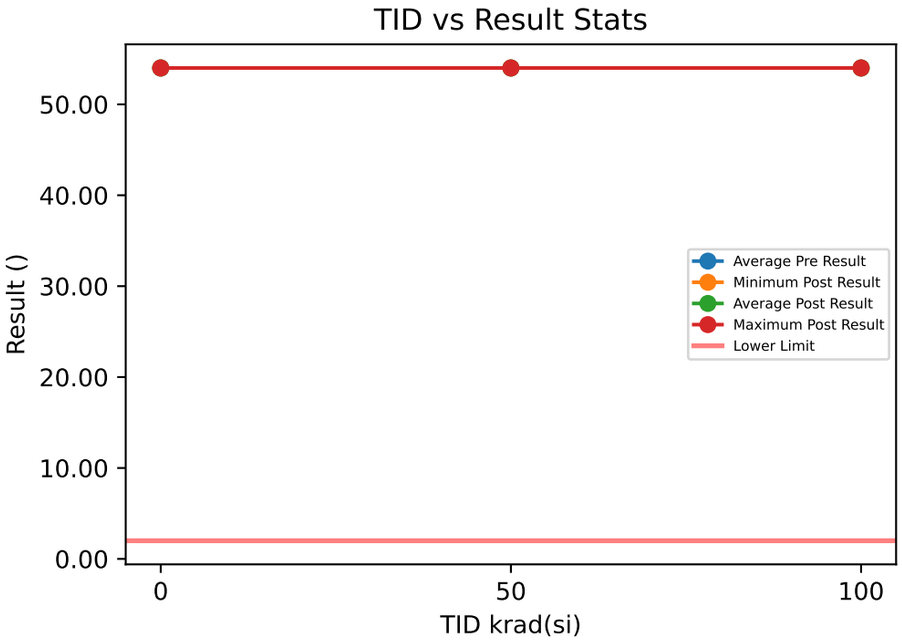
Test Results (Lower Limit = 2.0 ())

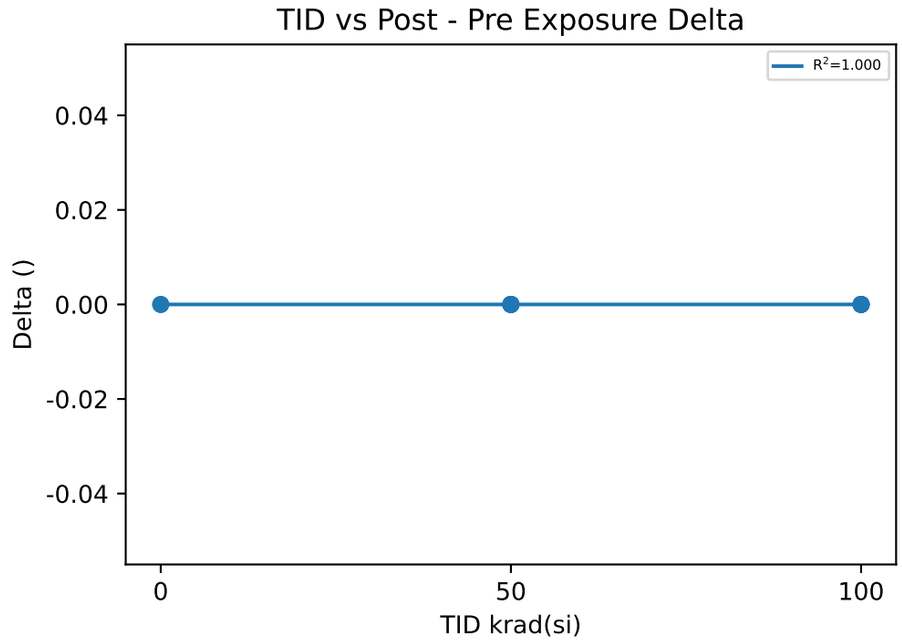
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	54	54	0
89	50	Biased	54	54	0
90	50	Biased	54	54	0
92	50	Biased	54	54	0
93	50	Unbiased	54	54	0
94	50	Unbiased	54	54	0
95	50	Unbiased	54	54	0
96	100	Biased	54	54	0
97	100	Biased	54	54	0
98	100	Biased	54	54	0
99	100	Unbiased	54	54	0
100	100	Unbiased	54	54	0
101	100	Unbiased	54	54	0
102	0	Correlation	54	54	0
103	0	Correlation	54	54	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	54	54	54	0	54	54	54	0	0	0	0	0
50	54	54	54	0	54	54	54	0	0	0	0	0
100	54	54	54	0	54	54	54	0	0	0	0	0

Device Test: 25.16 WDI_HT(T_MIN_R3_WDI/WDI/3.3/14/0/0/0/@WDI_HT)





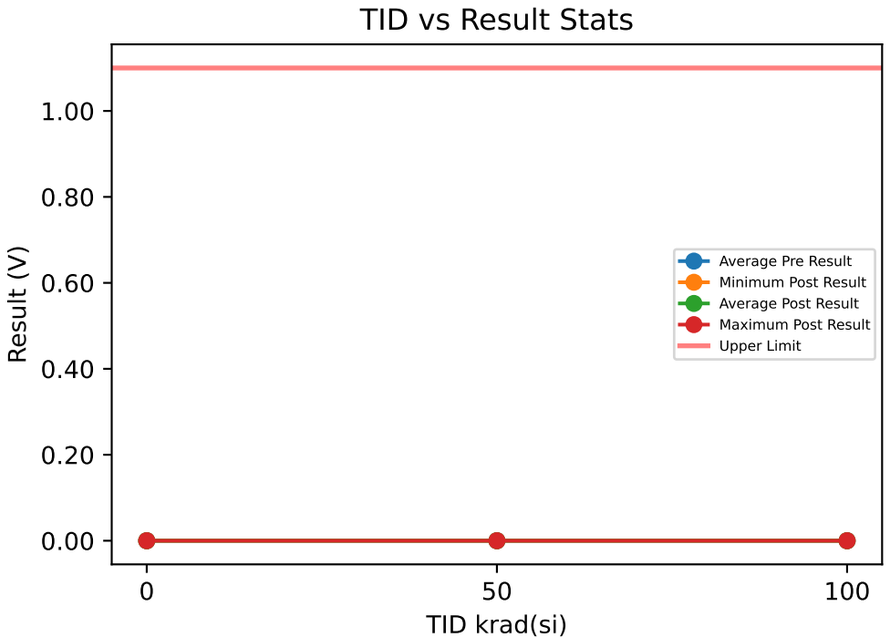
Test Results (Lower Limit = 2.0 ())

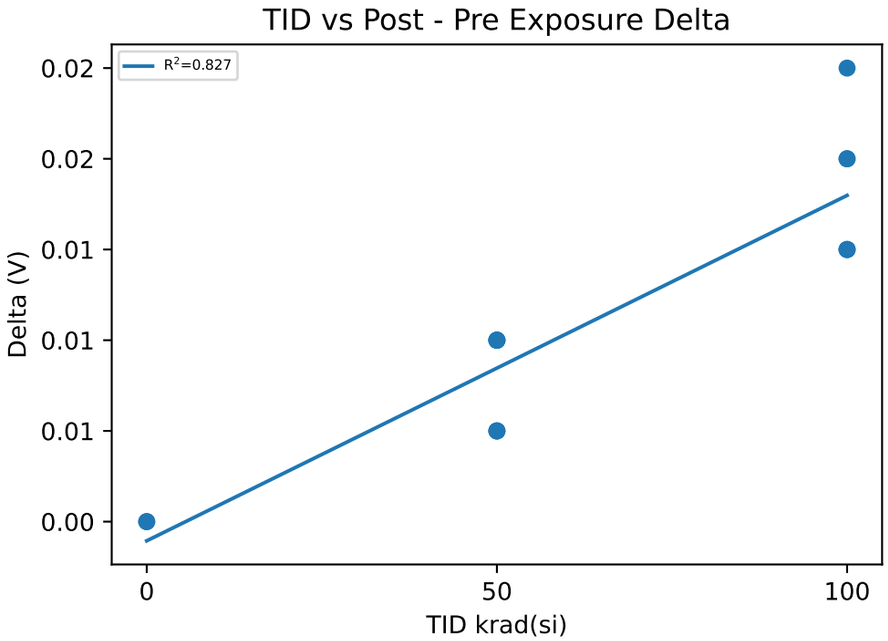
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	54	54	0
89	50	Biased	54	54	0
90	50	Biased	54	54	0
92	50	Biased	54	54	0
93	50	Unbiased	54	54	0
94	50	Unbiased	54	54	0
95	50	Unbiased	54	54	0
96	100	Biased	54	54	0
97	100	Biased	54	54	0
98	100	Biased	54	54	0
99	100	Unbiased	54	54	0
100	100	Unbiased	54	54	0
101	100	Unbiased	54	54	0
102	0	Correlation	54	54	0
103	0	Correlation	54	54	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	54	54	54	0	54	54	54	0	0	0	0	0
50	54	54	54	0	54	54	54	0	0	0	0	0
100	54	54	54	0	54	54	54	0	0	0	0	0

Device Test: 25.2 SR_UVLO_HT(T_MIN_SR/SR_UVLOB/3.3/14/0/0/0/@SR_UVLO_HT)





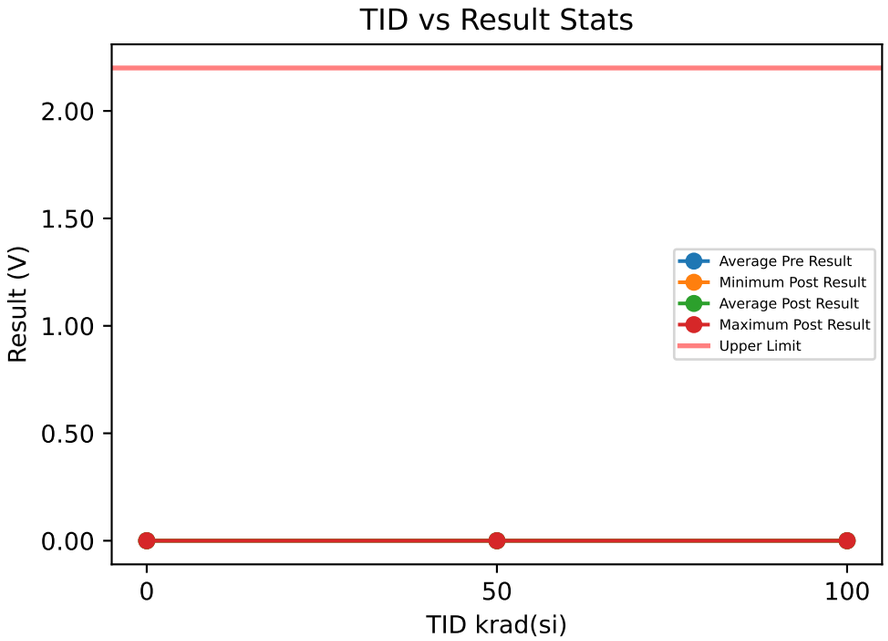
Test Results (Upper Limit = 1.1 (V))

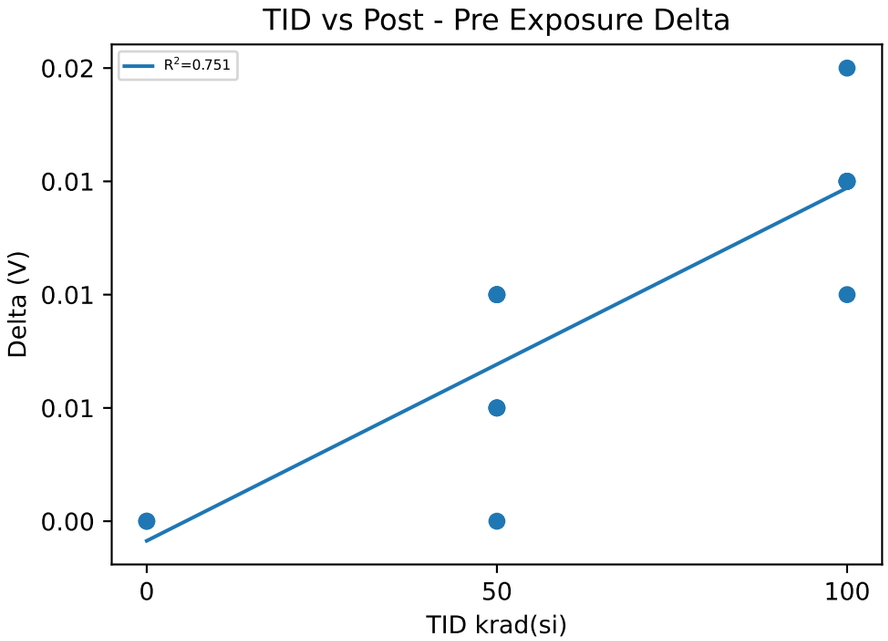
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	6.6e-07	6.65e-07	0.005
89	50	Biased	6.55e-07	6.65e-07	0.01
90	50	Biased	6.6e-07	6.65e-07	0.005
92	50	Biased	6.6e-07	6.65e-07	0.005
93	50	Unbiased	6.6e-07	6.7e-07	0.01
94	50	Unbiased	6.6e-07	6.7e-07	0.01
95	50	Unbiased	6.55e-07	6.65e-07	0.01
96	100	Biased	6.6e-07	6.75e-07	0.015
97	100	Biased	6.6e-07	6.75e-07	0.015
98	100	Biased	6.55e-07	6.7e-07	0.015
99	100	Unbiased	6.65e-07	6.85e-07	0.02
100	100	Unbiased	6.55e-07	6.75e-07	0.02
101	100	Unbiased	6.55e-07	6.8e-07	0.025
102	0	Correlation	6.6e-07	6.6e-07	0
103	0	Correlation	6.45e-07	6.45e-07	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.45e-07	6.525e-07	6.6e-07	1.0607e-08	6.45e-07	6.525e-07	6.6e-07	1.0607e-08	0	0	0	0
50	6.55e-07	6.5857e-07	6.6e-07	2.4398e-09	6.65e-07	6.6643e-07	6.7e-07	2.4398e-09	0.005	0.0078571	0.01	0.0026726
100	6.55e-07	6.5833e-07	6.65e-07	4.0825e-09	6.7e-07	6.7667e-07	6.85e-07	5.164e-09	0.015	0.018333	0.025	0.0040825

Device Test: 25.3 SENSE_F_HT_PP(T_MIN_SENSE/SENSE1/3.3/3/0/0/0/@SENSE_F_HT_PP)





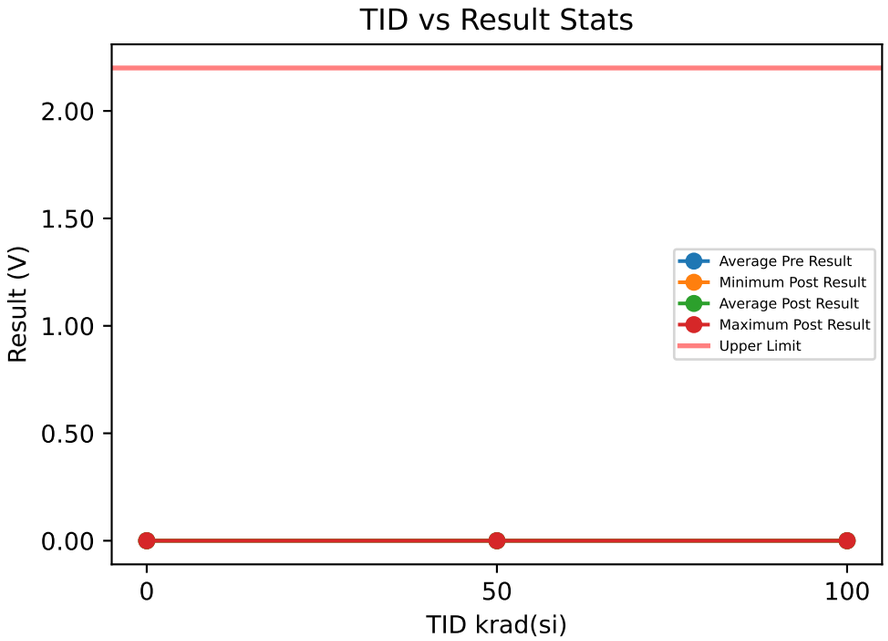
Test Results (Upper Limit = 2.2 (V))

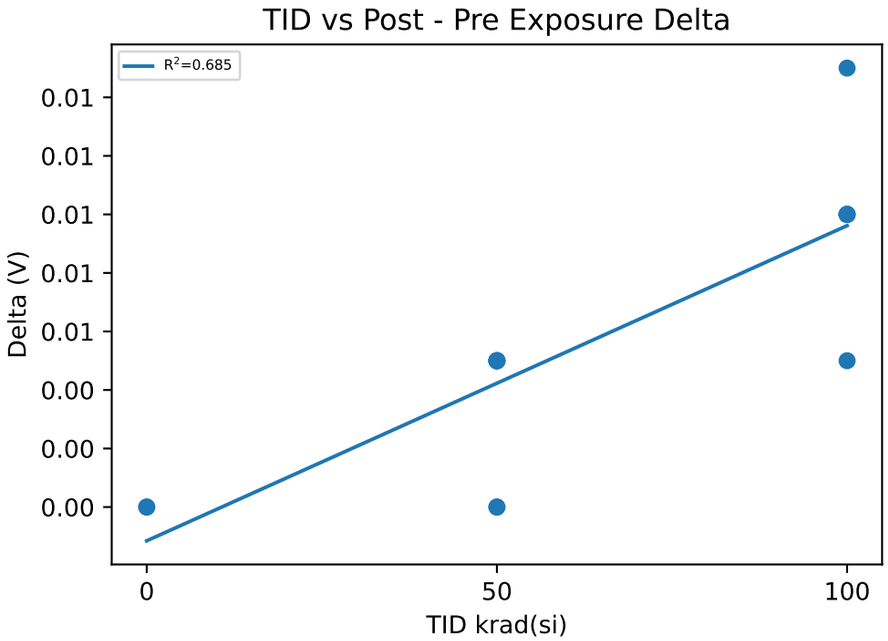
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	4.15e-07	4.15e-07	0
89	50	Biased	4.15e-07	4.25e-07	0.01
90	50	Biased	4.2e-07	4.25e-07	0.005
92	50	Biased	4.15e-07	4.2e-07	0.005
93	50	Unbiased	4.05e-07	4.1e-07	0.005
94	50	Unbiased	4.05e-07	4.15e-07	0.01
95	50	Unbiased	4.05e-07	4.15e-07	0.01
96	100	Biased	4.2e-07	4.3e-07	0.01
97	100	Biased	4.05e-07	4.2e-07	0.015
98	100	Biased	4.1e-07	4.25e-07	0.015
99	100	Unbiased	4.15e-07	4.3e-07	0.015
100	100	Unbiased	4.05e-07	4.25e-07	0.02
101	100	Unbiased	4.15e-07	4.3e-07	0.015
102	0	Correlation	4.05e-07	4.05e-07	0
103	0	Correlation	3.95e-07	3.95e-07	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.95e-07	4e-07	4.05e-07	7.0711e-09	3.95e-07	4e-07	4.05e-07	7.0711e-09	0	0	0	0
50	4.05e-07	4.1143e-07	4.2e-07	6.2678e-09	4.1e-07	4.1786e-07	4.25e-07	5.6695e-09	0	0.0064286	0.01	0.0037796
100	4.05e-07	4.1167e-07	4.2e-07	6.0553e-09	4.2e-07	4.2667e-07	4.3e-07	4.0825e-09	0.01	0.015	0.02	0.0031623

Device Test: 25.4 SENSE_F_HT_PP(T_MIN_SENSE/SENSE1/3.3/14/0/0/0/@SENSE_F_HT_PP)





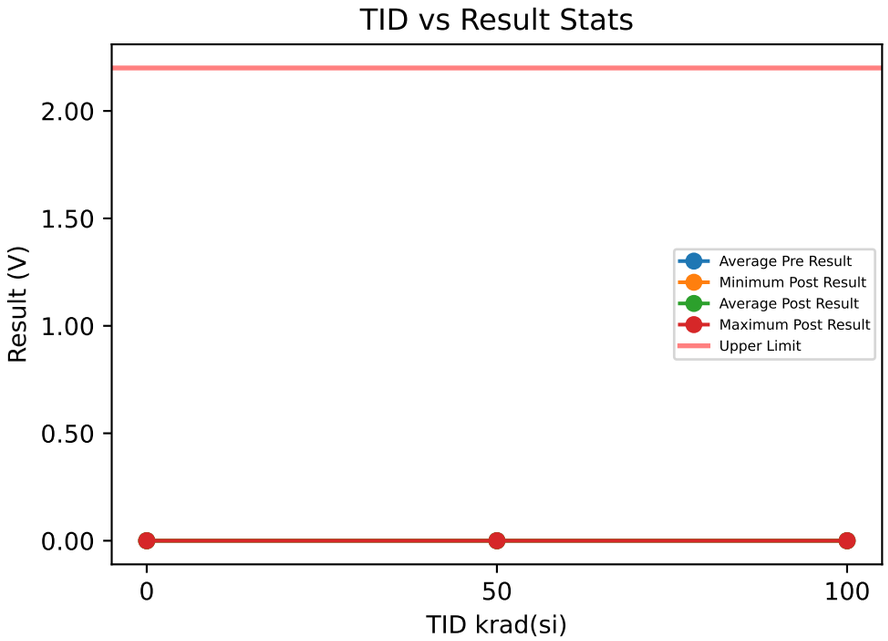
Test Results (Upper Limit = 2.2 (V))

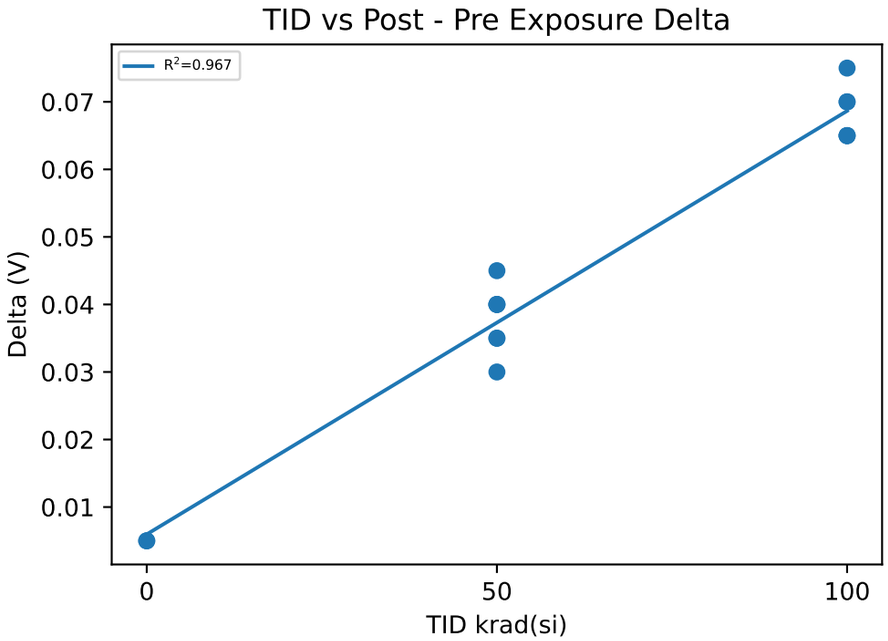
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	4.2e-07	4.2e-07	0
89	50	Biased	4.2e-07	4.25e-07	0.005
90	50	Biased	4.25e-07	4.3e-07	0.005
92	50	Biased	4.25e-07	4.25e-07	0
93	50	Unbiased	4.1e-07	4.15e-07	0.005
94	50	Unbiased	4.1e-07	4.15e-07	0.005
95	50	Unbiased	4.1e-07	4.15e-07	0.005
96	100	Biased	4.25e-07	4.3e-07	0.005
97	100	Biased	4.1e-07	4.25e-07	0.015
98	100	Biased	4.15e-07	4.25e-07	0.01
99	100	Unbiased	4.2e-07	4.3e-07	0.01
100	100	Unbiased	4.15e-07	4.25e-07	0.01
101	100	Unbiased	4.2e-07	4.3e-07	0.01
102	0	Correlation	4.1e-07	4.1e-07	0
103	0	Correlation	4e-07	4e-07	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4e-07	4.05e-07	4.1e-07	7.0711e-09	4e-07	4.05e-07	4.1e-07	7.0711e-09	0	0	0	0
50	4.1e-07	4.1714e-07	4.25e-07	6.9864e-09	4.15e-07	4.2071e-07	4.3e-07	6.0749e-09	0	0.0035714	0.005	0.0024398
100	4.1e-07	4.175e-07	4.25e-07	5.244e-09	4.25e-07	4.275e-07	4.3e-07	2.7386e-09	0.005	0.01	0.015	0.0031623

Device Test: 25.5 SENSE_F_HT_PP(T_MIN_SENSE/SENSE2/3.3/3/0/0/0/@SENSE_F_HT_PP)





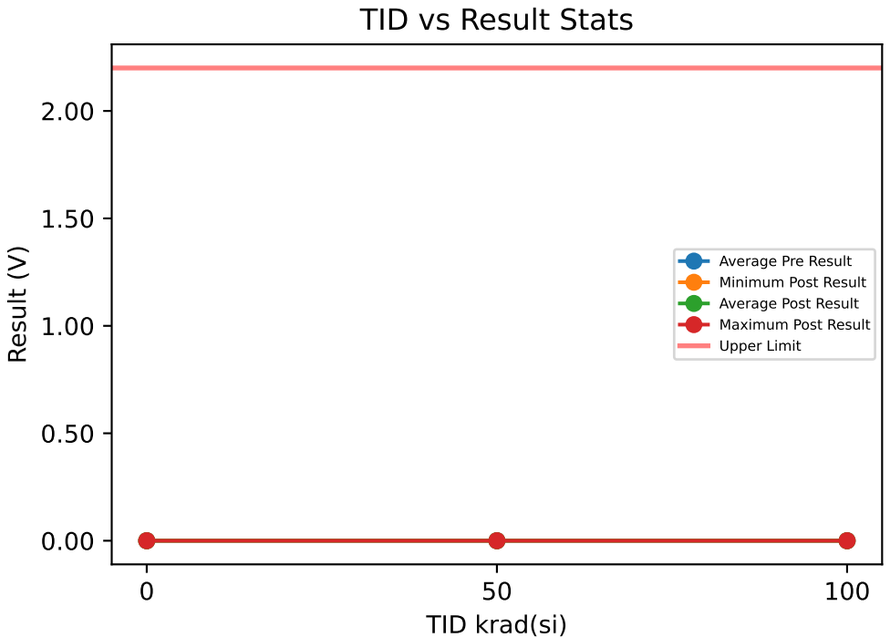
Test Results (Upper Limit = 2.2 (V))

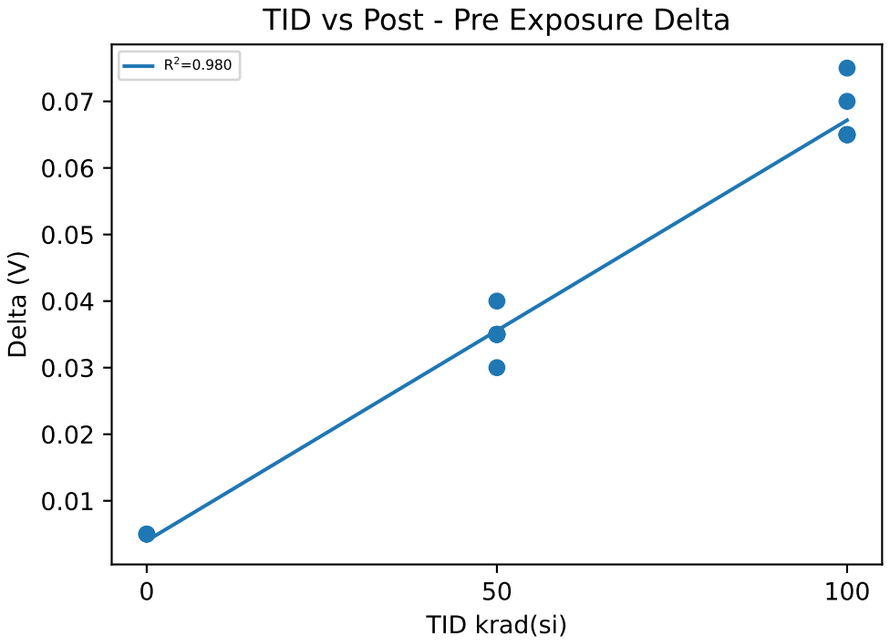
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	7.2e-07	7.55e-07	0.035
89	50	Biased	7.15e-07	7.55e-07	0.04
90	50	Biased	7e-07	7.45e-07	0.045
92	50	Biased	7.15e-07	7.55e-07	0.04
93	50	Unbiased	7.1e-07	7.5e-07	0.04
94	50	Unbiased	7.2e-07	7.5e-07	0.03
95	50	Unbiased	7.2e-07	7.55e-07	0.035
96	100	Biased	7.1e-07	7.75e-07	0.065
97	100	Biased	7.15e-07	7.8e-07	0.065
98	100	Biased	7.1e-07	7.85e-07	0.075
99	100	Unbiased	7.1e-07	7.8e-07	0.07
100	100	Unbiased	7.2e-07	7.85e-07	0.065
101	100	Unbiased	7.1e-07	7.8e-07	0.07
102	0	Correlation	7.05e-07	7.1e-07	0.005
103	0	Correlation	7.05e-07	7.1e-07	0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.05e-07	7.05e-07	7.05e-07	0	7.1e-07	7.1e-07	7.1e-07	0	0.005	0.005	0.005	0
50	7e-07	7.1429e-07	7.2e-07	7.3193e-09	7.45e-07	7.5214e-07	7.55e-07	3.934e-09	0.03	0.037857	0.045	0.0048795
100	7.1e-07	7.125e-07	7.2e-07	4.1833e-09	7.75e-07	7.8083e-07	7.85e-07	3.7639e-09	0.065	0.068333	0.075	0.0040825

Device Test: 25.6 SENSE_F_HT_PP(T_MIN_SENSE/SENSE2/3.3/14/0/0/0/@SENSE_F_HT_PP)





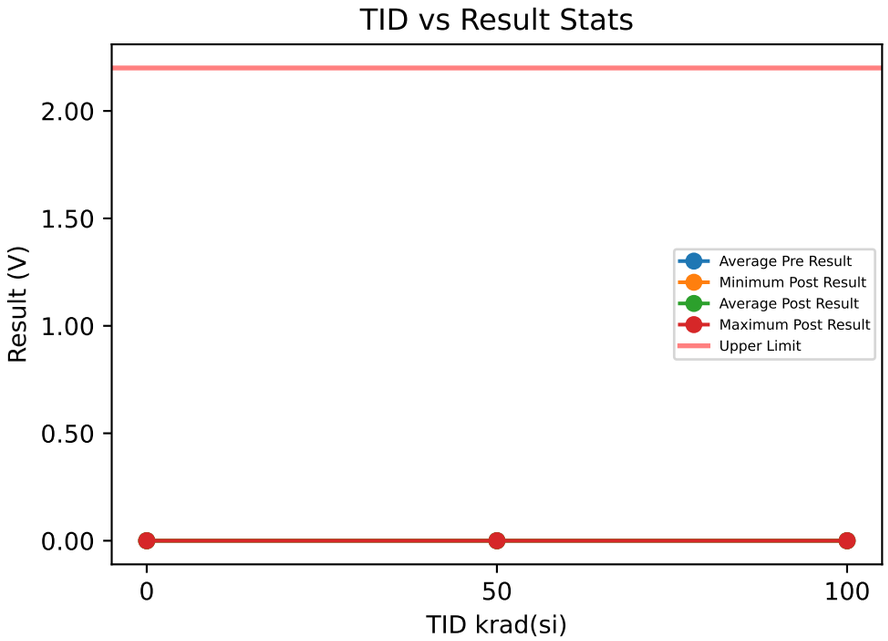
Test Results (Upper Limit = 2.2 (V))

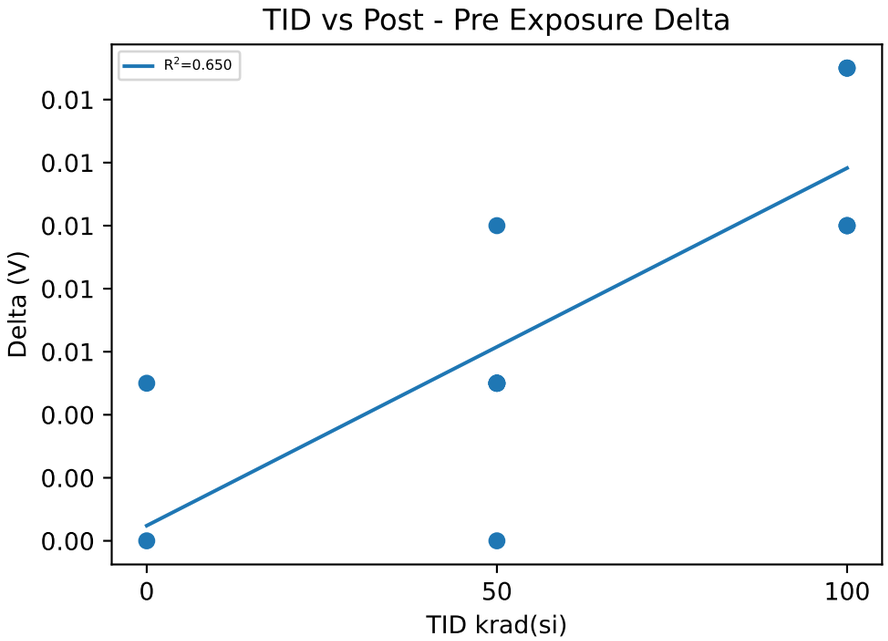
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	7.25e-07	7.6e-07	0.035
89	50	Biased	7.2e-07	7.55e-07	0.035
90	50	Biased	7.05e-07	7.45e-07	0.04
92	50	Biased	7.2e-07	7.55e-07	0.035
93	50	Unbiased	7.15e-07	7.5e-07	0.035
94	50	Unbiased	7.25e-07	7.55e-07	0.03
95	50	Unbiased	7.25e-07	7.6e-07	0.035
96	100	Biased	7.1e-07	7.8e-07	0.07
97	100	Biased	7.2e-07	7.85e-07	0.065
98	100	Biased	7.15e-07	7.9e-07	0.075
99	100	Unbiased	7.15e-07	7.8e-07	0.065
100	100	Unbiased	7.25e-07	7.9e-07	0.065
101	100	Unbiased	7.15e-07	7.8e-07	0.065
102	0	Correlation	7.1e-07	7.15e-07	0.005
103	0	Correlation	7.1e-07	7.15e-07	0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1e-07	7.1e-07	7.1e-07	0	7.15e-07	7.15e-07	7.15e-07	0	0.005	0.005	0.005	0
50	7.05e-07	7.1929e-07	7.25e-07	7.3193e-09	7.45e-07	7.5429e-07	7.6e-07	5.3452e-09	0.03	0.035	0.04	0.0028868
100	7.1e-07	7.1667e-07	7.25e-07	5.164e-09	7.8e-07	7.8417e-07	7.9e-07	4.916e-09	0.065	0.0675	0.075	0.0041833

Device Test: 25.7 SENSE_F_HT_PP(T_MIN_SENSE/SENSE3/3.3/3/0/0/0/@SENSE_F_HT_PP)





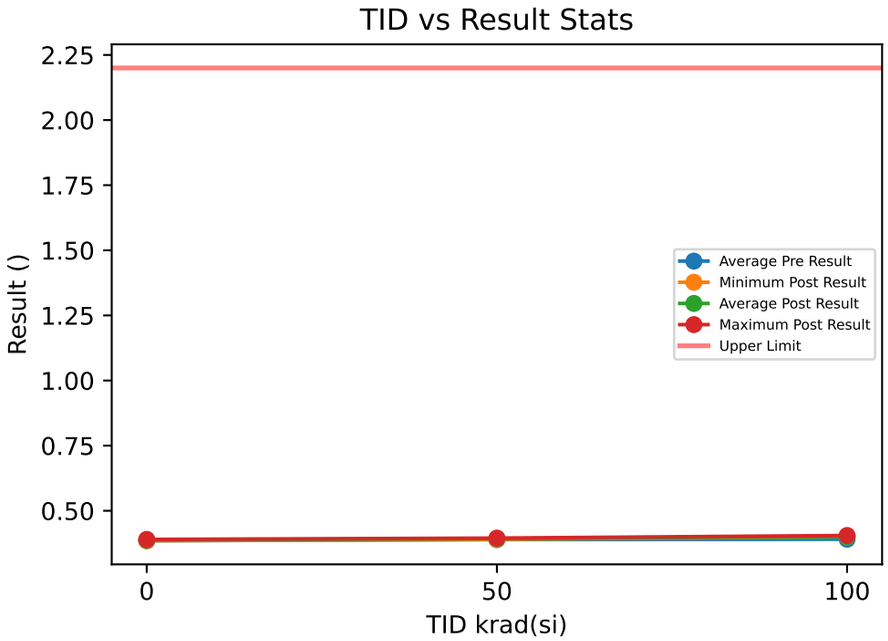
Test Results (Upper Limit = 2.2 (V))

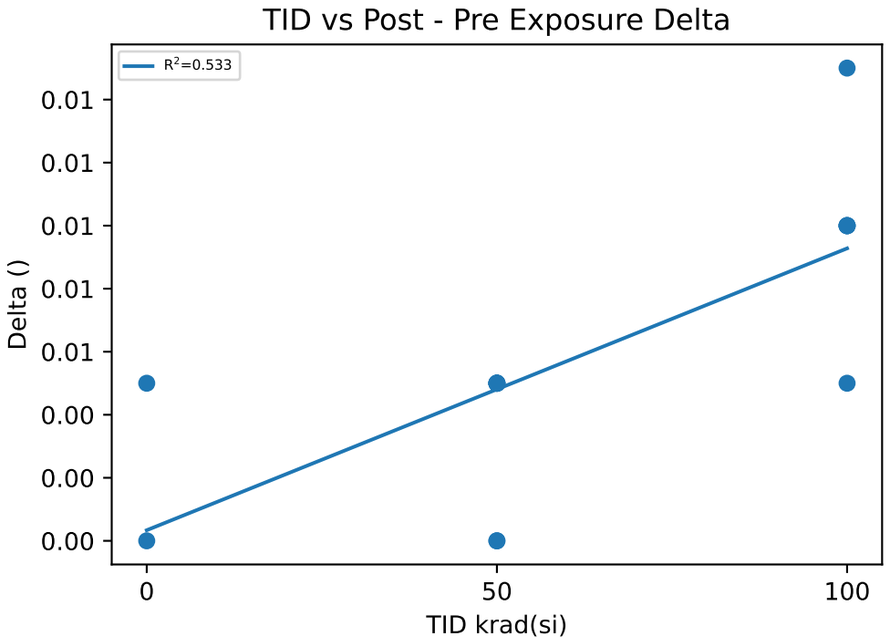
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	3.9e-07	3.95e-07	0.005
89	50	Biased	3.85e-07	3.9e-07	0.005
90	50	Biased	3.9e-07	3.9e-07	0
92	50	Biased	3.9e-07	3.95e-07	0.005
93	50	Unbiased	3.8e-07	3.85e-07	0.005
94	50	Unbiased	3.8e-07	3.9e-07	0.01
95	50	Unbiased	3.8e-07	3.85e-07	0.005
96	100	Biased	3.9e-07	4e-07	0.01
97	100	Biased	3.9e-07	4e-07	0.01
98	100	Biased	3.8e-07	3.95e-07	0.015
99	100	Unbiased	3.85e-07	3.95e-07	0.01
100	100	Unbiased	3.85e-07	4e-07	0.015
101	100	Unbiased	3.85e-07	4e-07	0.015
102	0	Correlation	3.8e-07	3.85e-07	0.005
103	0	Correlation	3.8e-07	3.8e-07	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.8e-07	3.8e-07	3.8e-07	0	3.8e-07	3.825e-07	3.85e-07	3.5355e-09	0	0.0025	0.005	0.0035355
50	3.8e-07	3.85e-07	3.9e-07	5e-09	3.85e-07	3.9e-07	3.95e-07	4.0825e-09	0	0.005	0.01	0.0028868
100	3.8e-07	3.8583e-07	3.9e-07	3.7639e-09	3.95e-07	3.9833e-07	4e-07	2.582e-09	0.01	0.0125	0.015	0.0027386

Device Test: 25.8 SENSE_F_HT_PP(T_MIN_SENSE/SENSE3/3.3/14/0/0/0/@SENSE_F_HT_PP)





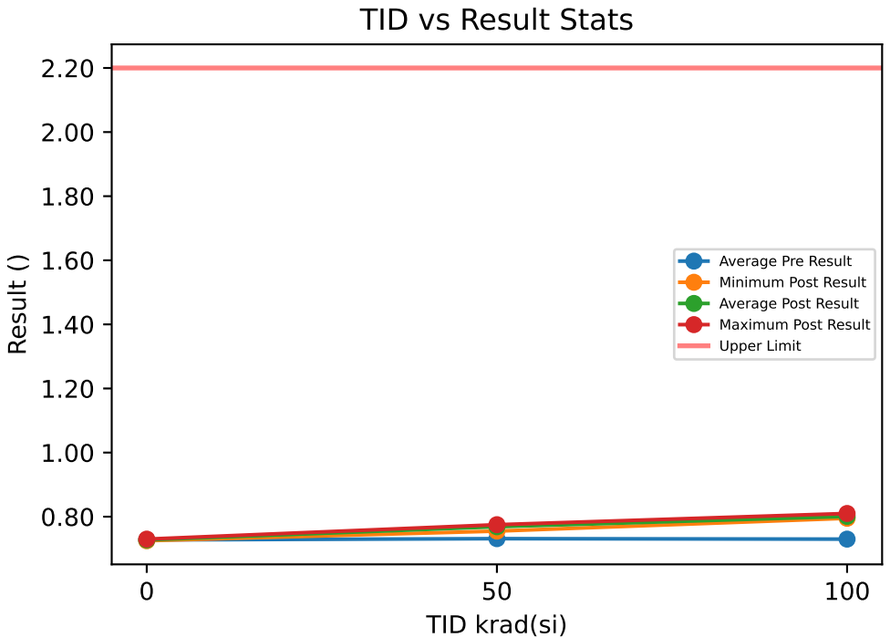
Test Results (Upper Limit = 2.2 ())

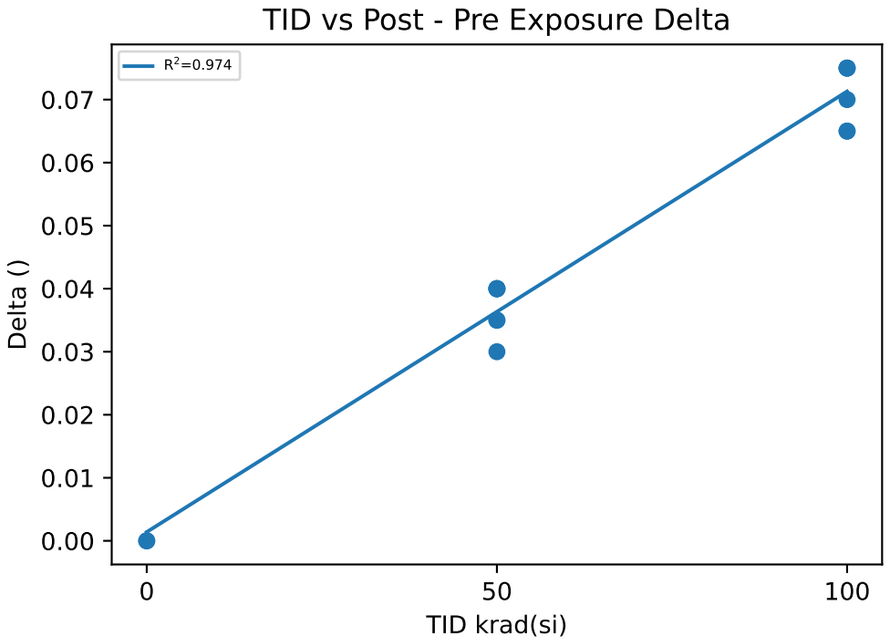
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.395	0.395	0
89	50	Biased	0.39	0.395	0.005
90	50	Biased	0.39	0.395	0.005
92	50	Biased	0.395	0.395	0
93	50	Unbiased	0.385	0.39	0.005
94	50	Unbiased	0.385	0.39	0.005
95	50	Unbiased	0.385	0.39	0.005
96	100	Biased	0.395	0.4	0.005
97	100	Biased	0.395	0.405	0.01
98	100	Biased	0.385	0.4	0.015
99	100	Unbiased	0.39	0.4	0.01
100	100	Unbiased	0.39	0.4	0.01
101	100	Unbiased	0.39	0.4	0.01
102	0	Correlation	0.385	0.39	0.005
103	0	Correlation	0.385	0.385	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.385	0.385	0.385	0	0.385	0.3875	0.39	0.0035355	0	0.0025	0.005	0.0035355
50	0.385	0.38929	0.395	0.0044987	0.39	0.39286	0.395	0.0026726	0	0.0035714	0.005	0.0024398
100	0.385	0.39083	0.395	0.0037639	0.4	0.40083	0.405	0.0020412	0.005	0.01	0.015	0.0031623

Device Test: 25.9 SENSE_F_HT_PP(T_MIN_SENSE/SENSE4/3.3/3/0/0/0/@SENSE_F_HT_PP)





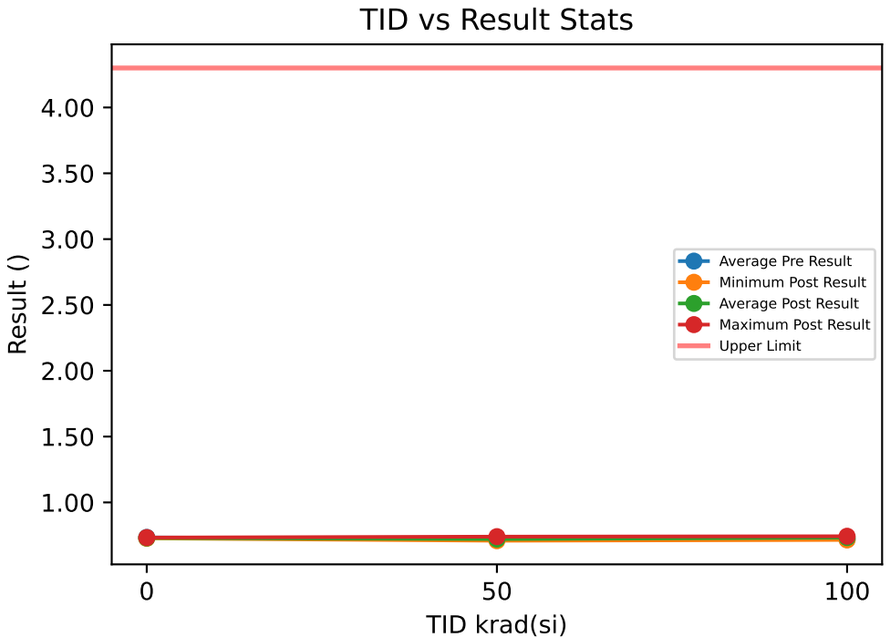
Test Results (Upper Limit = 2.2 ())

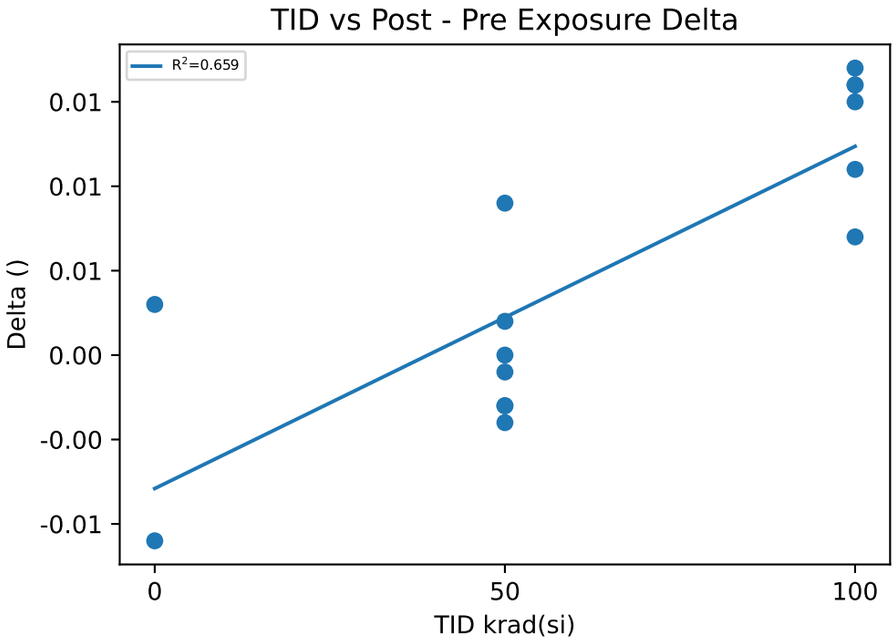
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.74	0.775	0.035
89	50	Biased	0.73	0.77	0.04
90	50	Biased	0.73	0.77	0.04
92	50	Biased	0.735	0.775	0.04
93	50	Unbiased	0.73	0.77	0.04
94	50	Unbiased	0.725	0.755	0.03
95	50	Unbiased	0.73	0.765	0.035
96	100	Biased	0.72	0.795	0.075
97	100	Biased	0.735	0.81	0.075
98	100	Biased	0.725	0.8	0.075
99	100	Unbiased	0.73	0.8	0.07
100	100	Unbiased	0.74	0.805	0.065
101	100	Unbiased	0.73	0.795	0.065
102	0	Correlation	0.73	0.73	0
103	0	Correlation	0.725	0.725	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.725	0.7275	0.73	0.0035355	0.725	0.7275	0.73	0.0035355	0	0	0	0
50	0.725	0.73143	0.74	0.0047559	0.755	0.76857	0.775	0.0069007	0.03	0.037143	0.04	0.003934
100	0.72	0.73	0.74	0.0070711	0.795	0.80083	0.81	0.0058452	0.065	0.070833	0.075	0.004916

Device Test: 5.0 PROPD_RESET(tpd_RESETB1_SU/RESETB1/1.6/3/0/0/0/@PROPD_RESET)





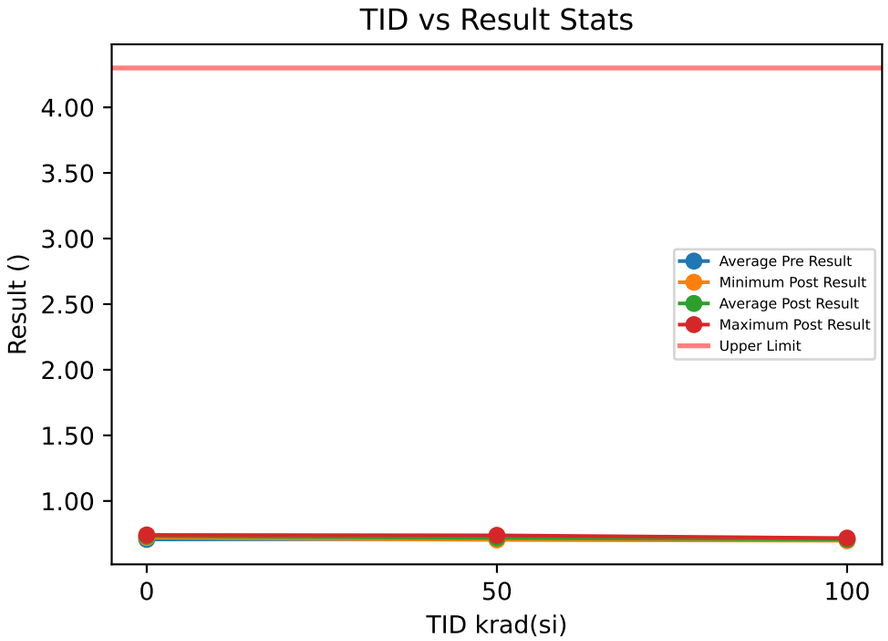
Test Results (Upper Limit = 4.3 ())

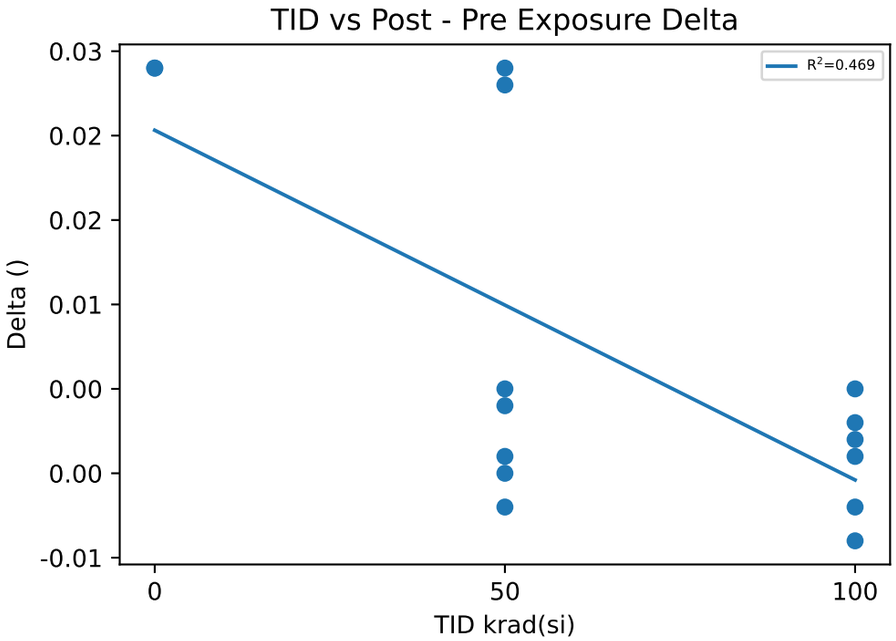
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.719	0.719	0
89	50	Biased	0.713	0.71	-0.003
90	50	Biased	0.71	0.709	-0.001
92	50	Biased	0.713	0.715	0.002
93	50	Unbiased	0.731	0.74	0.009
94	50	Unbiased	0.736	0.732	-0.004
95	50	Unbiased	0.727	0.724	-0.003
96	100	Biased	0.709	0.724	0.015
97	100	Biased	0.726	0.743	0.017
98	100	Biased	0.719	0.735	0.016
99	100	Unbiased	0.723	0.739	0.016
100	100	Unbiased	0.727	0.738	0.011
101	100	Unbiased	0.708	0.715	0.007
102	0	Correlation	0.724	0.727	0.003
103	0	Correlation	0.744	0.733	-0.011

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.724	0.734	0.744	0.014142	0.727	0.73	0.733	0.0042426	-0.011	-0.004	0.003	0.0098995
50	0.71	0.72129	0.736	0.010111	0.709	0.72129	0.74	0.011514	-0.004	0	0.009	0.0044721
100	0.708	0.71867	0.727	0.0083586	0.715	0.73233	0.743	0.010652	0.007	0.013667	0.017	0.0038816

Device Test: 5.1 PROPD_RESET(tpd_RESETB3_SU/RESETB3/1.6/3/0/0/0/@PROPD_RESET)





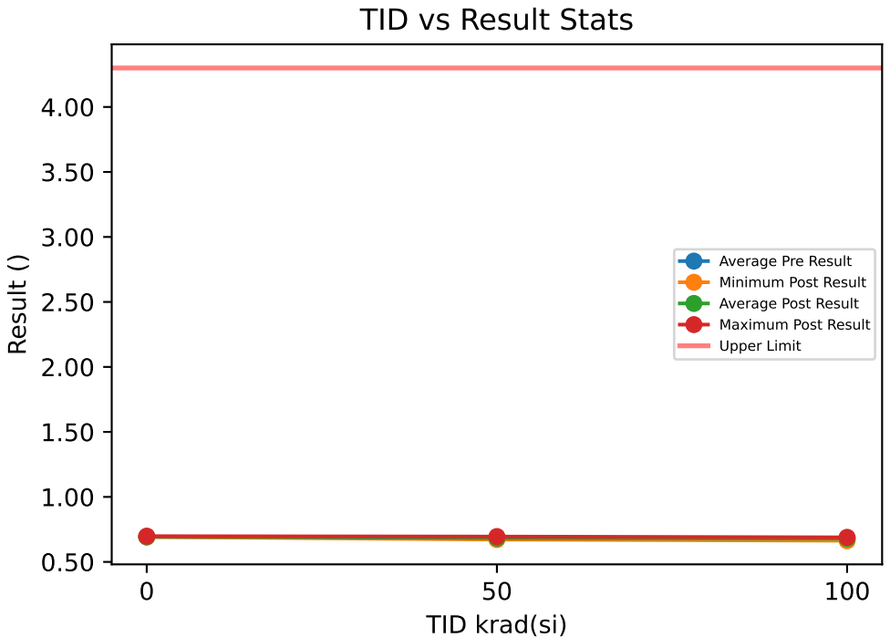
Test Results (Upper Limit = 4.3 ())

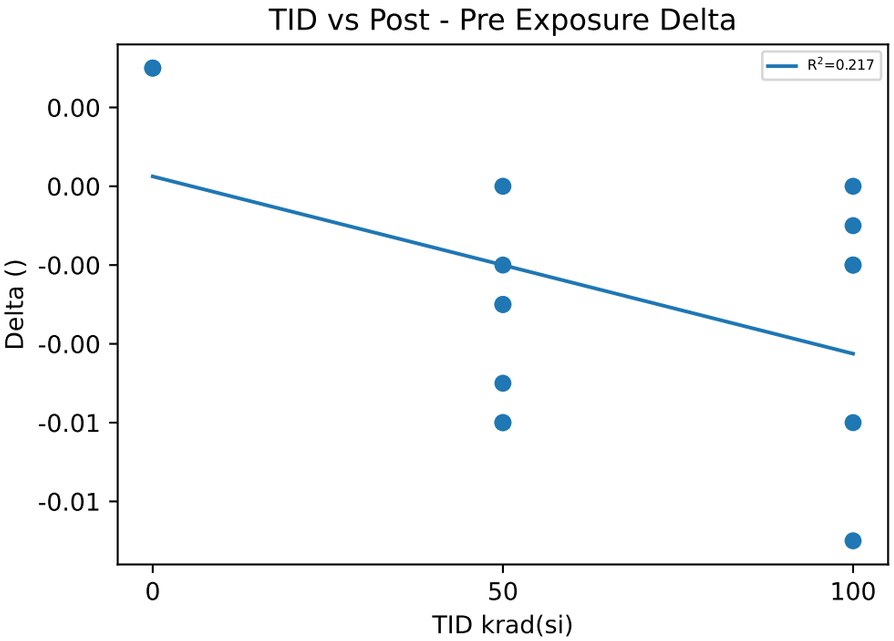
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.703	0.704	0.001
89	50	Biased	0.712	0.712	0
90	50	Biased	0.701	0.725	0.024
92	50	Biased	0.699	0.703	0.004
93	50	Unbiased	0.72	0.725	0.005
94	50	Unbiased	0.715	0.738	0.023
95	50	Unbiased	0.723	0.721	-0.002
96	100	Biased	0.694	0.697	0.003
97	100	Biased	0.709	0.711	0.002
98	100	Biased	0.713	0.709	-0.004
99	100	Unbiased	0.709	0.707	-0.002
100	100	Unbiased	0.716	0.717	0.001
101	100	Unbiased	0.694	0.699	0.005
102	0	Correlation	0.717	0.741	0.024
103	0	Correlation	0.697	0.721	0.024

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.697	0.707	0.717	0.014142	0.721	0.731	0.741	0.014142	0.024	0.024	0.024	0
50	0.699	0.71043	0.723	0.0095544	0.703	0.71829	0.738	0.012672	-0.002	0.0078571	0.024	0.010946
100	0.694	0.70583	0.716	0.0095376	0.697	0.70667	0.717	0.0075277	-0.004	0.00083333	0.005	0.0033116

Device Test: 5.10 PROPD_RESET(tpd_RESETB1_SU/RESETB1/7/3/0/0/0/@PROPD_RESET)





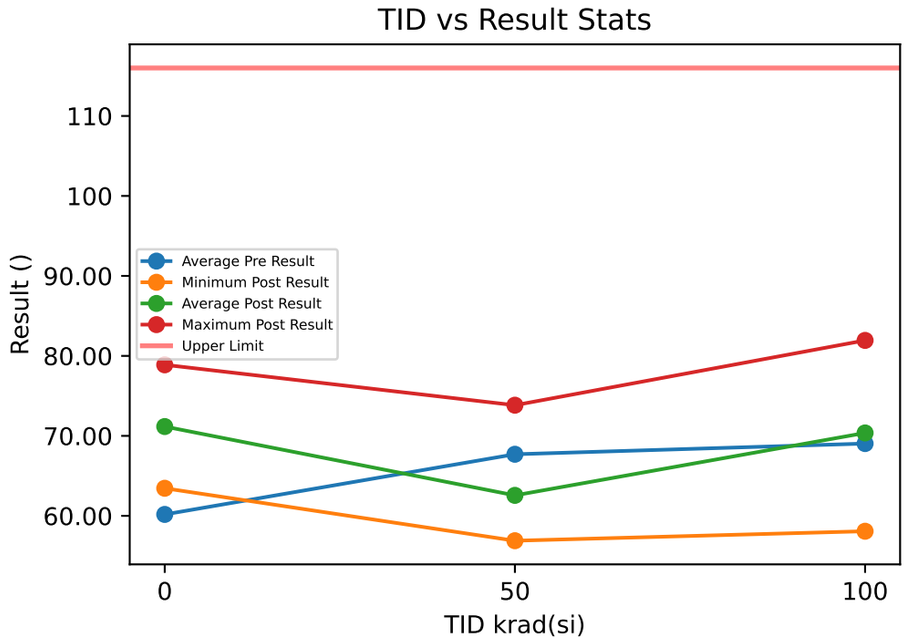
Test Results (Upper Limit = 4.3 ())

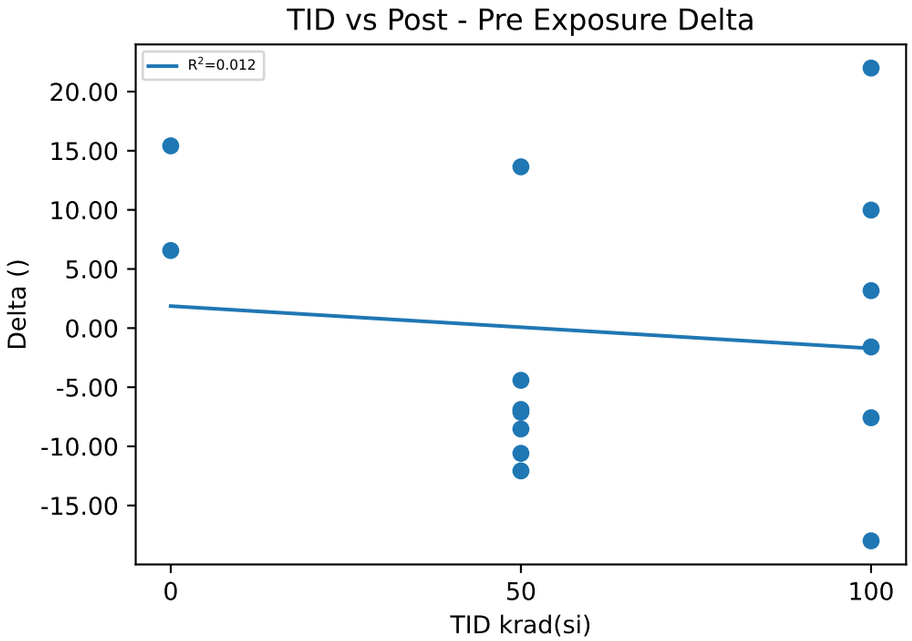
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.684	0.682	-0.002
89	50	Biased	0.677	0.674	-0.003
90	50	Biased	0.675	0.672	-0.003
92	50	Biased	0.677	0.677	0
93	50	Unbiased	0.695	0.69	-0.005
94	50	Unbiased	0.701	0.695	-0.006
95	50	Unbiased	0.693	0.687	-0.006
96	100	Biased	0.674	0.672	-0.002
97	100	Biased	0.69	0.689	-0.001
98	100	Biased	0.683	0.683	0
99	100	Unbiased	0.688	0.686	-0.002
100	100	Unbiased	0.691	0.685	-0.006
101	100	Unbiased	0.672	0.663	-0.009
102	0	Correlation	0.689	0.692	0.003
103	0	Correlation	0.695	0.698	0.003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.689	0.692	0.695	0.0042426	0.692	0.695	0.698	0.0042426	0.003	0.003	0.003	0
50	0.675	0.686	0.701	0.010344	0.672	0.68243	0.695	0.0086189	-0.006	-0.0035714	0	0.0022254
100	0.672	0.683	0.691	0.0082462	0.663	0.67967	0.689	0.010033	-0.009	-0.0033333	0	0.0034448

Device Test: 5.100 PROPD_WDO_1P5(tpd_WDI_SU/WDOB/1.6/3/0/0/0/@PROPD_WDO_1P5)





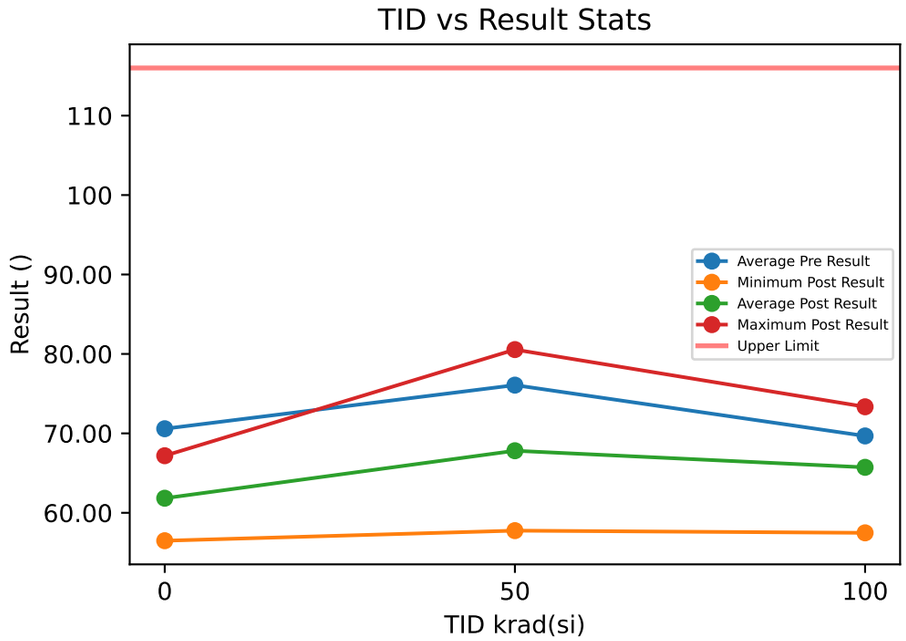
Test Results (Upper Limit = 116.0 ())

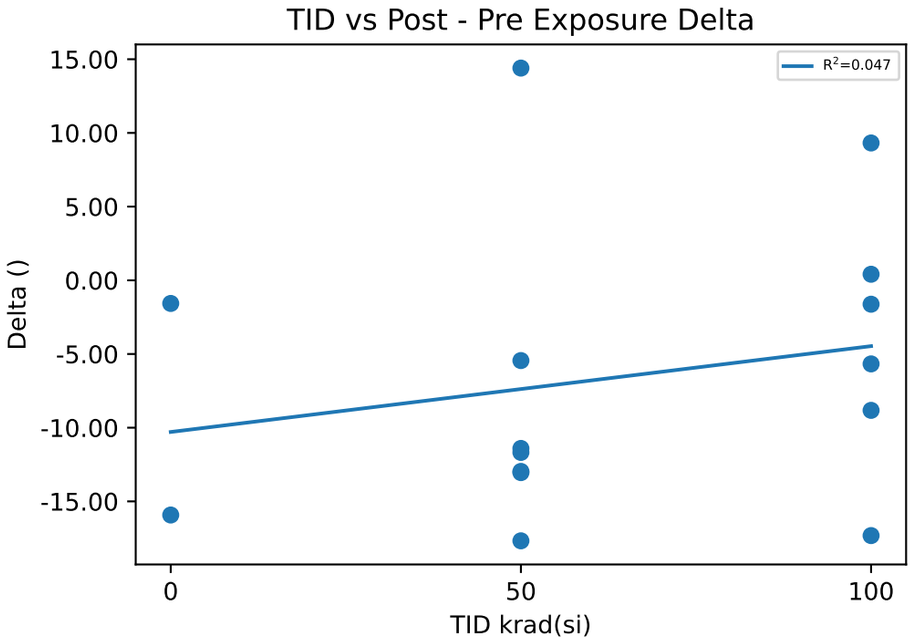
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	68.473	64.056	-4.417
89	50	Biased	70.72	62.189	-8.531
90	50	Biased	68.25	61.135	-7.115
92	50	Biased	69.632	57.557	-12.075
93	50	Unbiased	69.15	62.267	-6.883
94	50	Unbiased	67.482	56.89	-10.592
95	50	Unbiased	60.197	73.835	13.638
96	100	Biased	74.028	77.196	3.168
97	100	Biased	65.655	58.075	-7.58
98	100	Biased	81.177	63.188	-17.989
99	100	Unbiased	68.542	78.522	9.98
100	100	Unbiased	59.946	81.936	21.99
101	100	Unbiased	64.878	63.282	-1.596
102	0	Correlation	56.886	63.448	6.562
103	0	Correlation	63.47	78.883	15.413

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	56.886	60.178	63.47	4.6556	63.448	71.165	78.883	10.914	6.562	10.987	15.413	6.2586
50	60.197	67.701	70.72	3.4689	56.89	62.561	73.835	5.6095	-12.075	-5.1393	13.638	8.6544
100	59.946	69.038	81.177	7.5355	58.075	70.367	81.936	9.9981	-17.989	1.3288	21.99	13.901

Device Test: 5.101 PROPD_WDO_1P5(tpd_WDI_SU/WDOB/1.6/14/0/0/0/@PROPD_WDO_1P5)





Test Results (Upper Limit = 116.0 ())

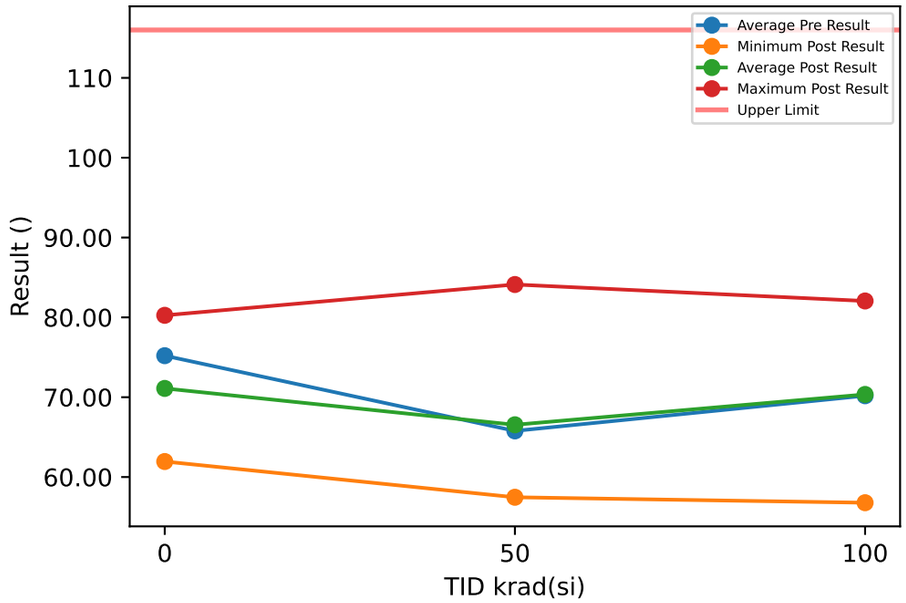
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	80.856	69.448	-11.408
89	50	Biased	76.175	63.208	-12.967
90	50	Biased	80.316	68.638	-11.678
92	50	Biased	75.43	57.754	-17.676
93	50	Unbiased	76.098	70.652	-5.446
94	50	Unbiased	77.485	64.437	-13.048
95	50	Unbiased	66.147	80.547	14.4
96	100	Biased	57.066	57.477	0.411
97	100	Biased	74.767	65.943	-8.824
98	100	Biased	62.075	71.393	9.318
99	100	Unbiased	77.496	60.175	-17.321
100	100	Unbiased	71.683	66.011	-5.672
101	100	Unbiased	74.968	73.346	-1.622
102	0	Correlation	68.755	67.185	-1.57
103	0	Correlation	72.41	56.485	-15.925

Test Statistics ()

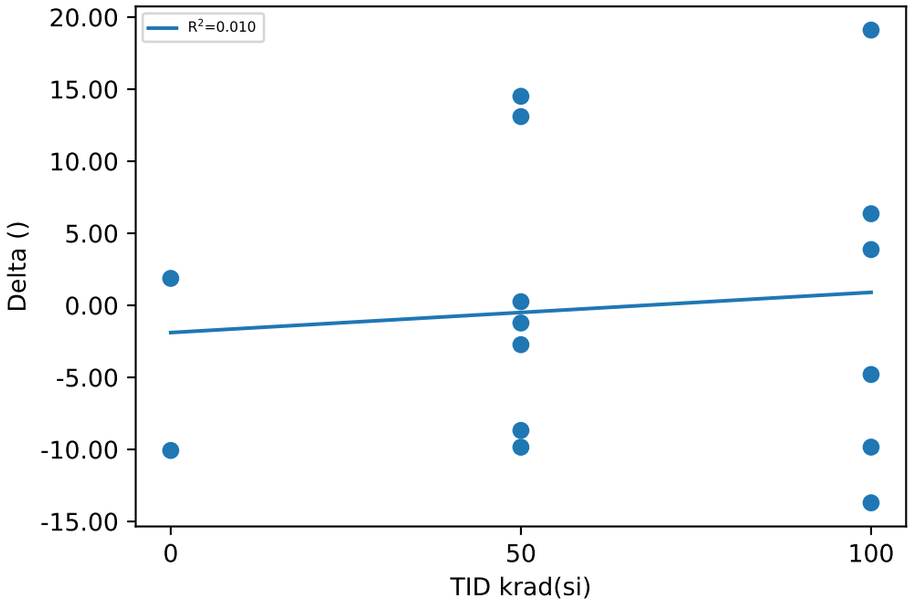
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	68.755	70.582	72.41	2.5845	56.485	61.835	67.185	7.566	-15.925	-8.7475	-1.57	10.151
50	66.147	76.072	80.856	4.8618	57.754	67.812	80.547	7.1572	-17.676	-8.2604	14.4	10.62
100	57.066	69.676	77.496	8.1962	57.477	65.724	73.346	6.1509	-17.321	-3.9517	9.318	9.0109

Device Test: 5.102 PROPD_WDO_1P5(tpd_WDI_SU/WDOB/7/3/0/0/0/@PROPD_WDO_1P5)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



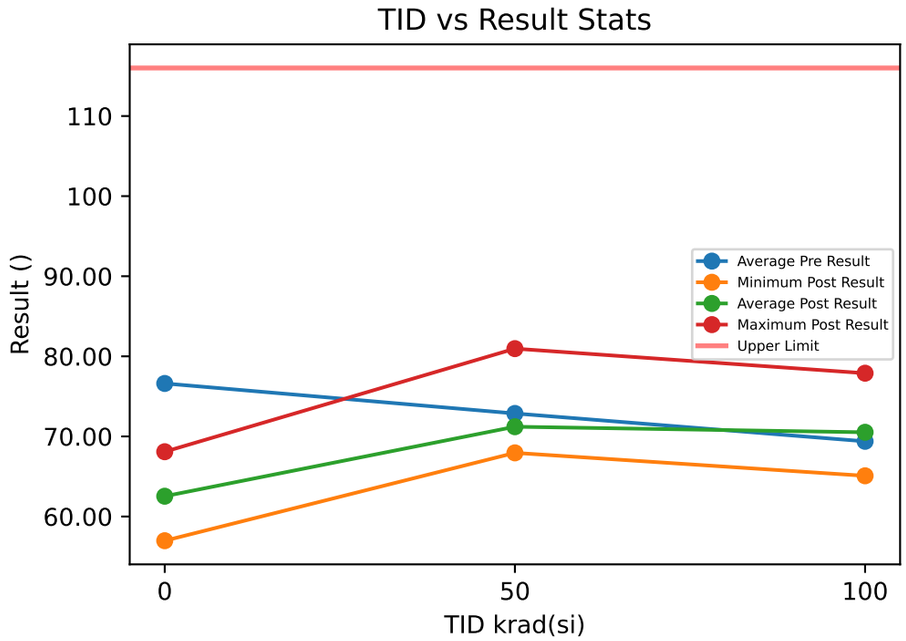
Test Results (Upper Limit = 116.0 ())

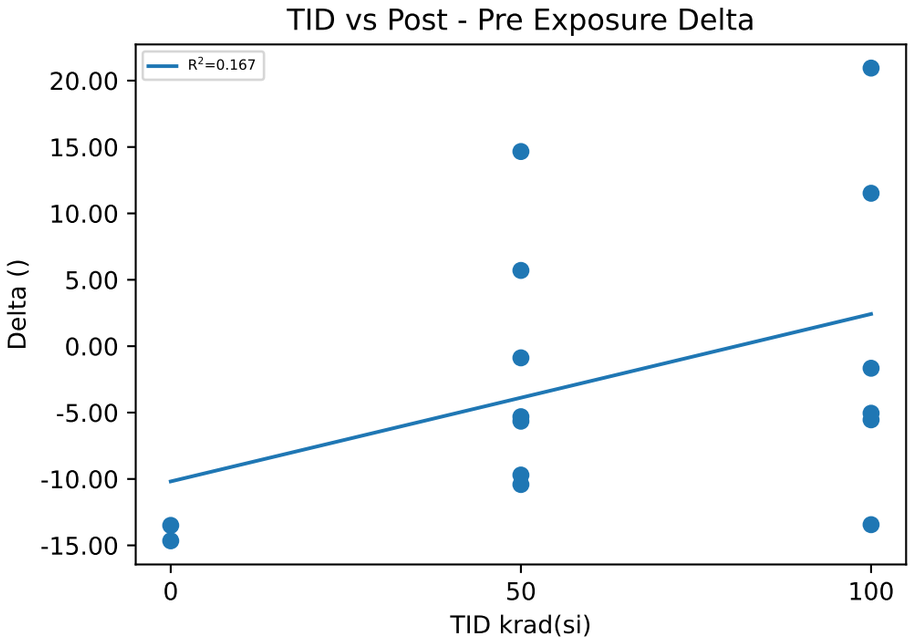
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	67.973	59.291	-8.682
89	50	Biased	67.545	64.813	-2.732
90	50	Biased	62.699	62.951	0.252
92	50	Biased	67.314	57.467	-9.847
93	50	Unbiased	63.321	62.093	-1.228
94	50	Unbiased	71.018	84.116	13.098
95	50	Unbiased	60.581	75.088	14.507
96	100	Biased	73.933	80.29	6.357
97	100	Biased	62.951	82.054	19.103
98	100	Biased	80.55	66.843	-13.707
99	100	Unbiased	72.117	75.985	3.868
100	100	Unbiased	66.625	56.783	-9.842
101	100	Unbiased	64.922	60.121	-4.801
102	0	Correlation	72.015	61.943	-10.072
103	0	Correlation	78.387	80.257	1.87

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	72.015	75.201	78.387	4.5057	61.943	71.1	80.257	12.95	-10.072	-4.101	1.87	8.4443
50	60.581	65.779	71.018	3.6579	57.467	66.546	84.116	9.5959	-9.847	0.76686	14.507	9.6546
100	62.951	70.183	80.55	6.6018	56.783	70.346	82.054	10.663	-13.707	0.163	19.103	12.066

Device Test: 5.103 PROPD_WDO_1P5(tpd_WDI_SU/WDOB/7/14/0/0/0/@PROPD_WDO_1P5)





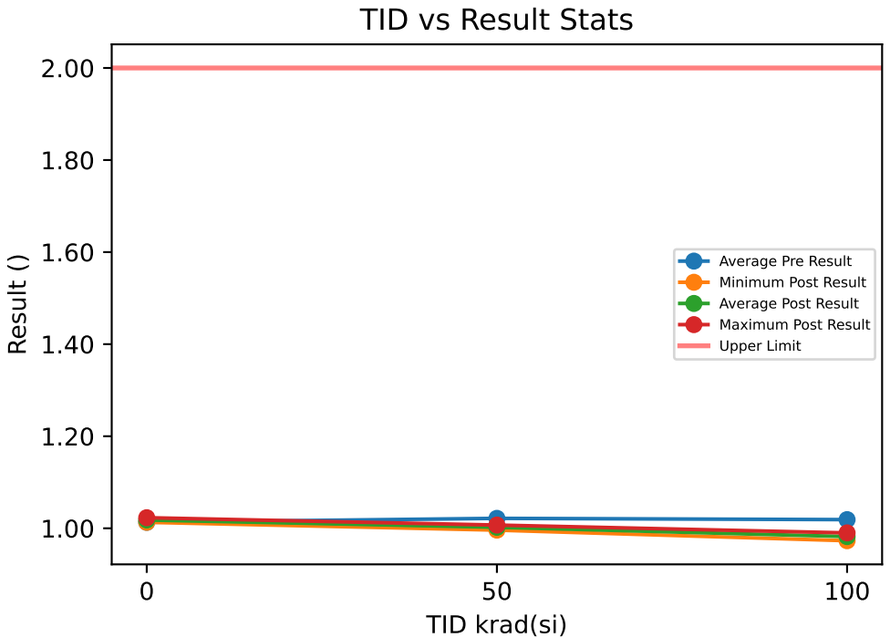
Test Results (Upper Limit = 116.0 ())

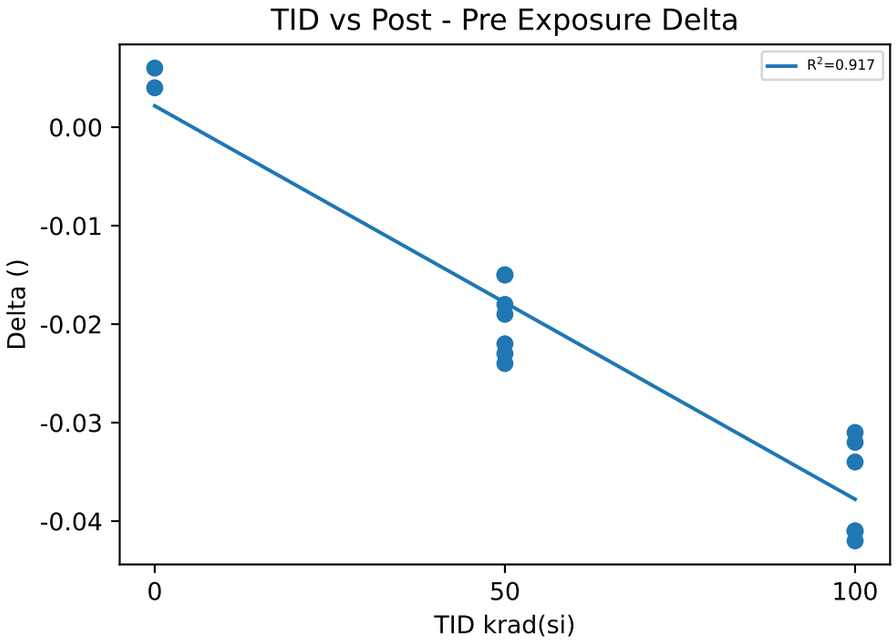
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	62.243	67.948	5.705
89	50	Biased	73.026	72.148	-0.878
90	50	Biased	77.822	68.118	-9.704
92	50	Biased	79.181	68.763	-10.418
93	50	Unbiased	75.25	69.94	-5.31
94	50	Unbiased	76.24	70.59	-5.65
95	50	Unbiased	66.3	80.959	14.659
96	100	Biased	56.948	77.892	20.944
97	100	Biased	71.571	66.026	-5.545
98	100	Biased	57.688	69.204	11.516
99	100	Unbiased	78.642	76.981	-1.661
100	100	Unbiased	72.963	67.914	-5.049
101	100	Unbiased	78.525	65.083	-13.442
102	0	Correlation	81.586	68.089	-13.497
103	0	Correlation	71.636	56.978	-14.658

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	71.636	76.611	81.586	7.0357	56.978	62.534	68.089	7.8567	-14.658	-14.077	-13.497	0.82095
50	62.243	72.866	79.181	6.2915	67.948	71.209	80.959	4.5481	-10.418	-1.6566	14.659	9.0537
100	56.948	69.389	78.642	9.7807	65.083	70.517	77.892	5.5565	-13.442	1.1272	20.944	12.675

Device Test: 5.104 PROPD_SR_UVLO(tpd_SR_UVLOB_SU/SR_UVLOB/1.6/3/0/0/0/@PROPD_SR_UVLO)





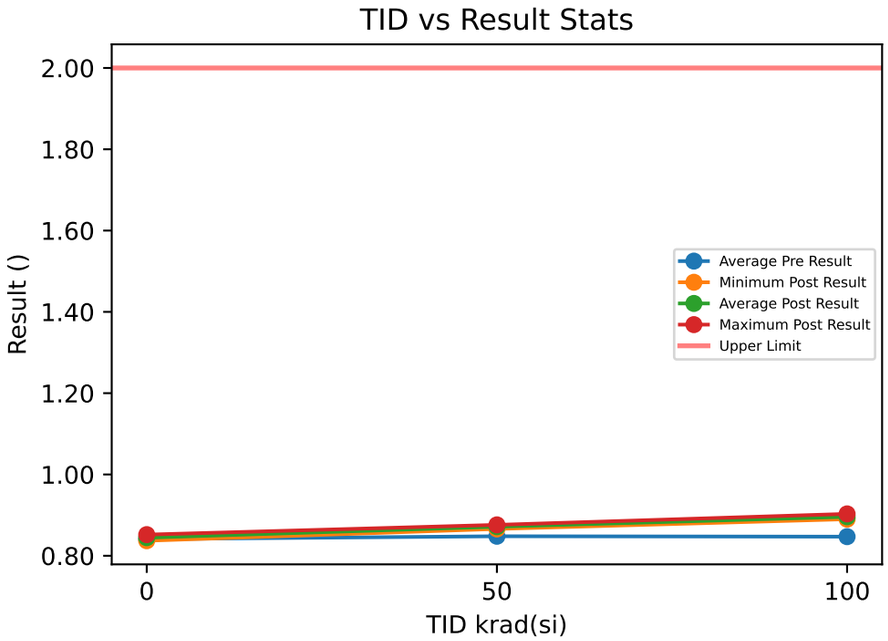
Test Results (Upper Limit = 2.0 ())

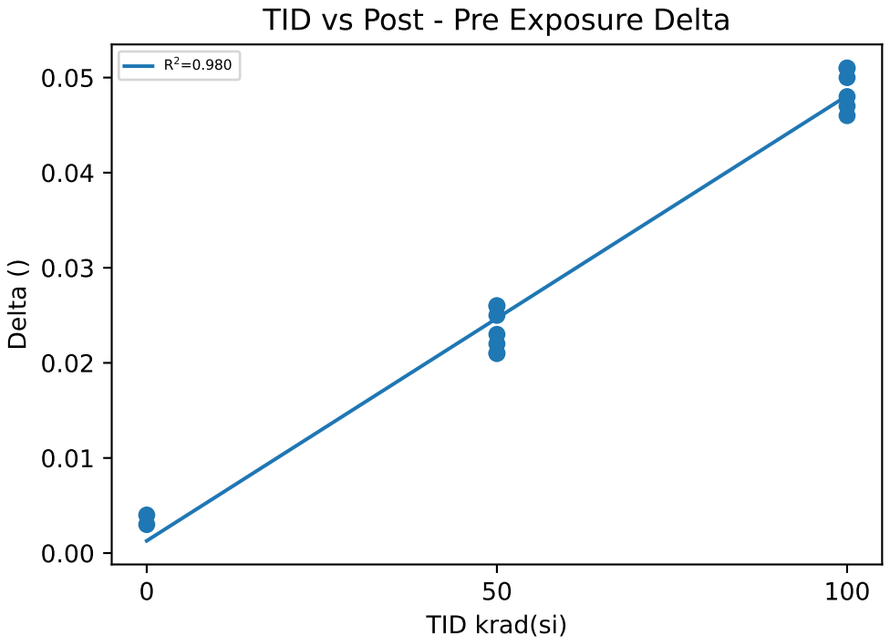
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.018	1.003	-0.015
89	50	Biased	1.017	1.002	-0.015
90	50	Biased	1.021	1.002	-0.019
92	50	Biased	1.025	1.007	-0.018
93	50	Unbiased	1.018	0.996	-0.022
94	50	Unbiased	1.028	1.005	-0.023
95	50	Unbiased	1.024	1	-0.024
96	100	Biased	1.021	0.99	-0.031
97	100	Biased	1.021	0.989	-0.032
98	100	Biased	1.017	0.983	-0.034
99	100	Unbiased	1.02	0.979	-0.041
100	100	Unbiased	1.014	0.973	-0.041
101	100	Unbiased	1.02	0.978	-0.042
102	0	Correlation	1.017	1.023	0.006
103	0	Correlation	1.009	1.013	0.004

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.009	1.013	1.017	0.0056569	1.013	1.018	1.023	0.0070711	0.004	0.005	0.006	0.0014142
50	1.017	1.0216	1.028	0.0041975	0.996	1.0021	1.007	0.0035322	-0.024	-0.019429	-0.015	0.0036904
100	1.014	1.0188	1.021	0.0027869	0.973	0.982	0.99	0.0066332	-0.042	-0.036833	-0.031	0.0050365

Device Test: 5.105 PROPD_SR_UVLO(tpd_SR_UVLOB_SD/SR_UVLOB/1.6/3/0/0/0/@PROPD_SR_UVLO)





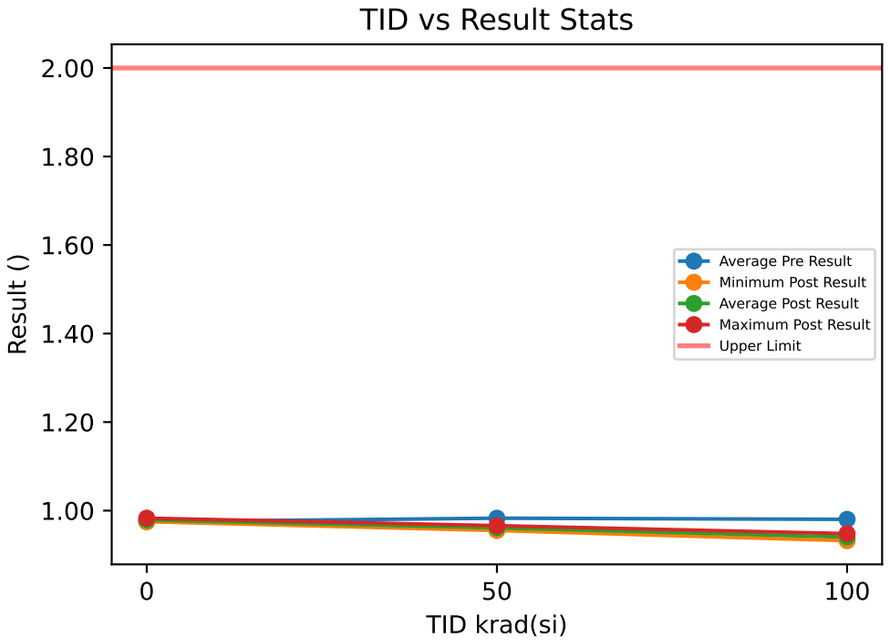
Test Results (Upper Limit = 2.0 ())

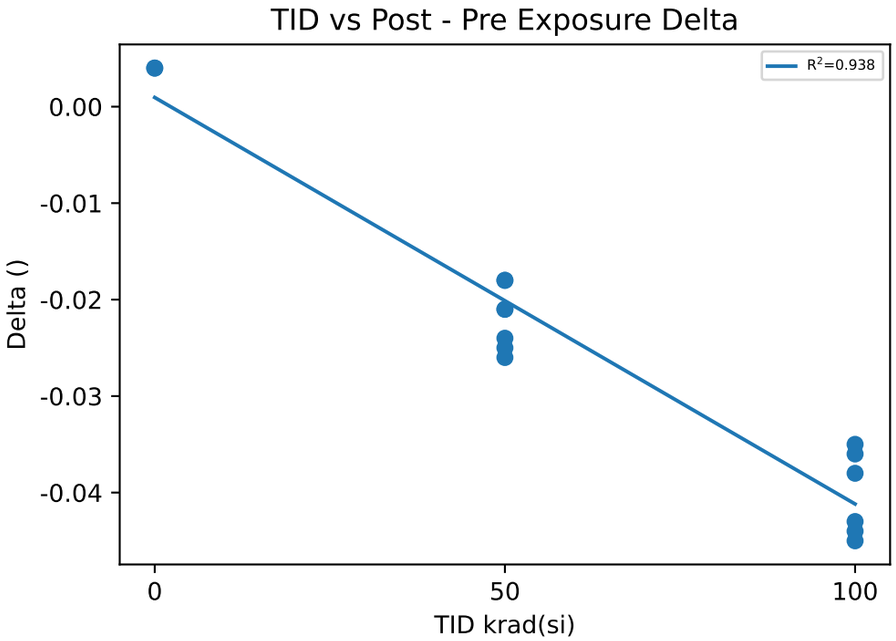
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.85	0.871	0.021
89	50	Biased	0.844	0.866	0.022
90	50	Biased	0.851	0.872	0.021
92	50	Biased	0.847	0.87	0.023
93	50	Unbiased	0.85	0.876	0.026
94	50	Unbiased	0.85	0.875	0.025
95	50	Unbiased	0.844	0.87	0.026
96	100	Biased	0.849	0.895	0.046
97	100	Biased	0.85	0.898	0.048
98	100	Biased	0.843	0.89	0.047
99	100	Unbiased	0.852	0.903	0.051
100	100	Unbiased	0.842	0.892	0.05
101	100	Unbiased	0.846	0.897	0.051
102	0	Correlation	0.848	0.852	0.004
103	0	Correlation	0.834	0.837	0.003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.834	0.841	0.848	0.0098995	0.837	0.8445	0.852	0.010607	0.003	0.0035	0.004	0.00070711
50	0.844	0.848	0.851	0.003	0.866	0.87143	0.876	0.0033594	0.021	0.023429	0.026	0.0022254
100	0.842	0.847	0.852	0.004	0.89	0.89583	0.903	0.0046224	0.046	0.048833	0.051	0.002137

Device Test: 5.106 PROPD_SR_UVLO(tpd_SR_UVLOB_SU/SR_UVLOB/1.6/14/0/0/0/@PROPD_SR_UVLO)





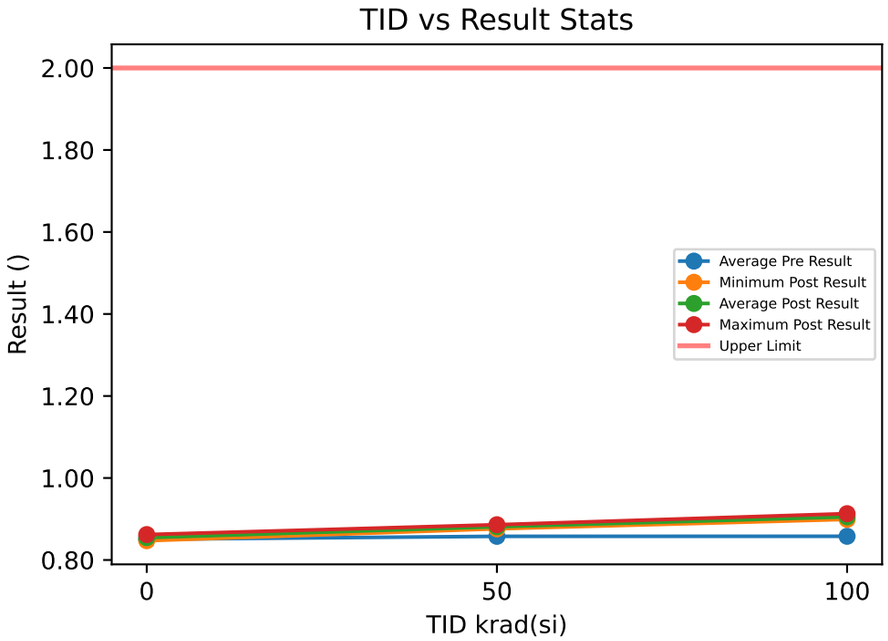
Test Results (Upper Limit = 2.0 ())

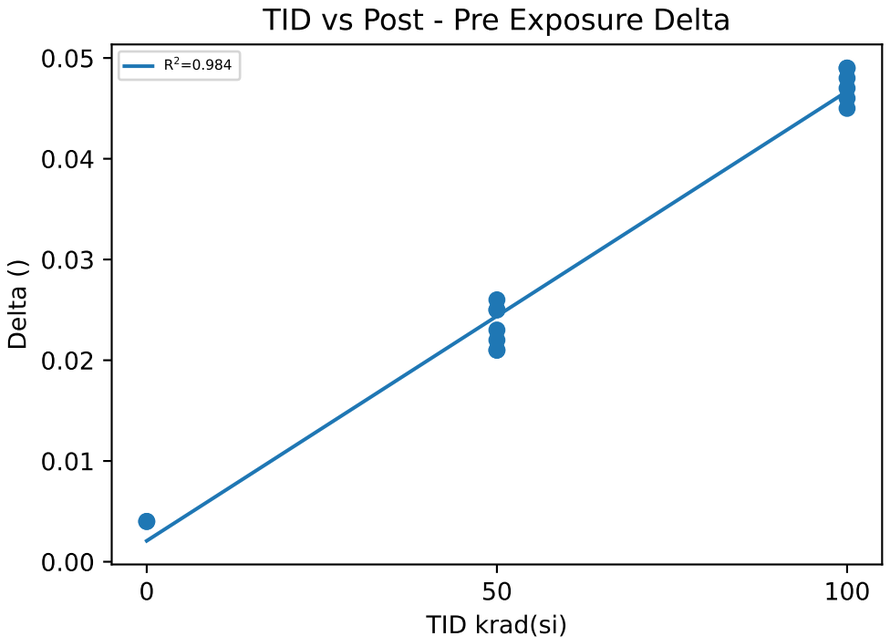
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.98	0.962	-0.018
89	50	Biased	0.978	0.96	-0.018
90	50	Biased	0.981	0.96	-0.021
92	50	Biased	0.986	0.965	-0.021
93	50	Unbiased	0.979	0.955	-0.024
94	50	Unbiased	0.991	0.966	-0.025
95	50	Unbiased	0.985	0.959	-0.026
96	100	Biased	0.983	0.948	-0.035
97	100	Biased	0.982	0.946	-0.036
98	100	Biased	0.979	0.941	-0.038
99	100	Unbiased	0.982	0.938	-0.044
100	100	Unbiased	0.975	0.932	-0.043
101	100	Unbiased	0.981	0.936	-0.045
102	0	Correlation	0.979	0.983	0.004
103	0	Correlation	0.971	0.975	0.004

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.971	0.975	0.979	0.0056569	0.975	0.979	0.983	0.0056569	0.004	0.004	0.004	0
50	0.978	0.98286	0.991	0.0046701	0.955	0.961	0.966	0.0037417	-0.026	-0.021857	-0.018	0.0032367
100	0.975	0.98033	0.983	0.0029439	0.932	0.94017	0.948	0.00608	-0.045	-0.040167	-0.035	0.0043551

Device Test: 5.107 PROPD_SR_UVLO(tpd_SR_UVLOB_SD/SR_UVLOB/1.6/14/0/0/0/@PROPD_SR_UVLO)





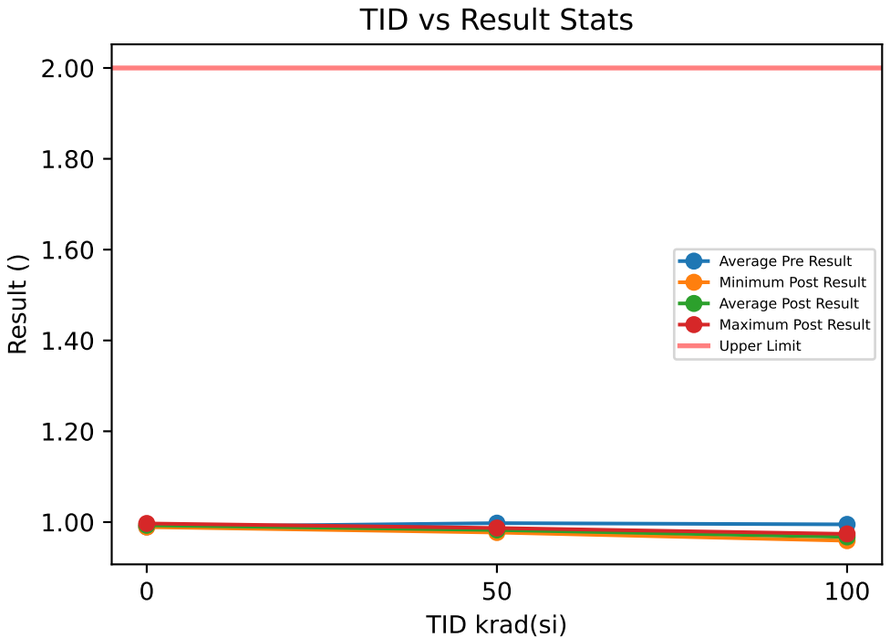
Test Results (Upper Limit = 2.0 ())

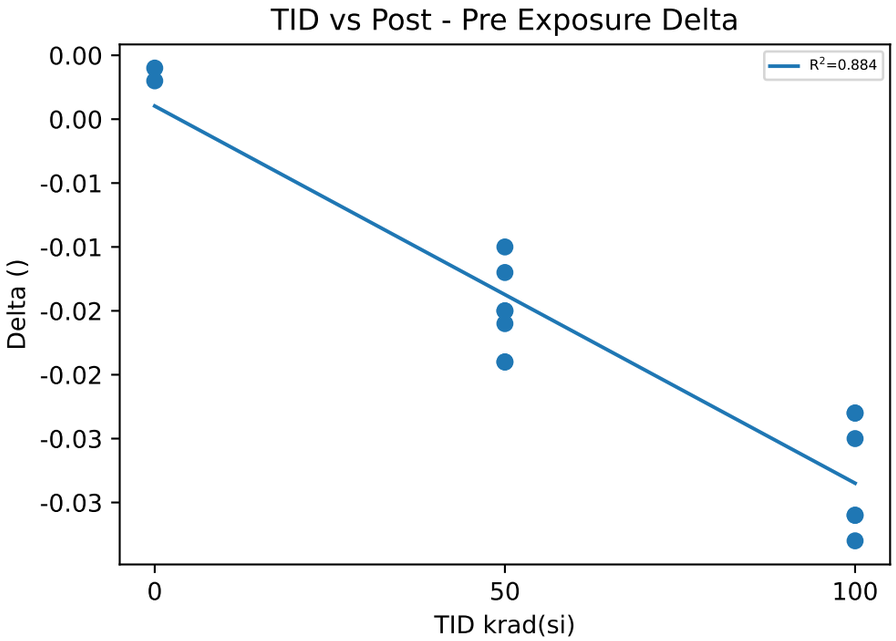
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.86	0.881	0.021
89	50	Biased	0.853	0.876	0.023
90	50	Biased	0.86	0.882	0.022
92	50	Biased	0.858	0.879	0.021
93	50	Unbiased	0.86	0.886	0.026
94	50	Unbiased	0.859	0.884	0.025
95	50	Unbiased	0.854	0.879	0.025
96	100	Biased	0.86	0.905	0.045
97	100	Biased	0.86	0.907	0.047
98	100	Biased	0.853	0.899	0.046
99	100	Unbiased	0.864	0.913	0.049
100	100	Unbiased	0.853	0.901	0.048
101	100	Unbiased	0.857	0.906	0.049
102	0	Correlation	0.858	0.862	0.004
103	0	Correlation	0.843	0.847	0.004

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.843	0.8505	0.858	0.010607	0.847	0.8545	0.862	0.010607	0.004	0.004	0.004	0
50	0.853	0.85771	0.86	0.0029841	0.876	0.881	0.886	0.0033665	0.021	0.023286	0.026	0.0020587
100	0.853	0.85783	0.864	0.0043551	0.899	0.90517	0.913	0.004916	0.045	0.047333	0.049	0.001633

Device Test: 5.108 PROPD_SR_UVLO(tpd_SR_UVLOB_SU/SR_UVLOB/7/3/0/0/0/@PROPD_SR_UVLO)





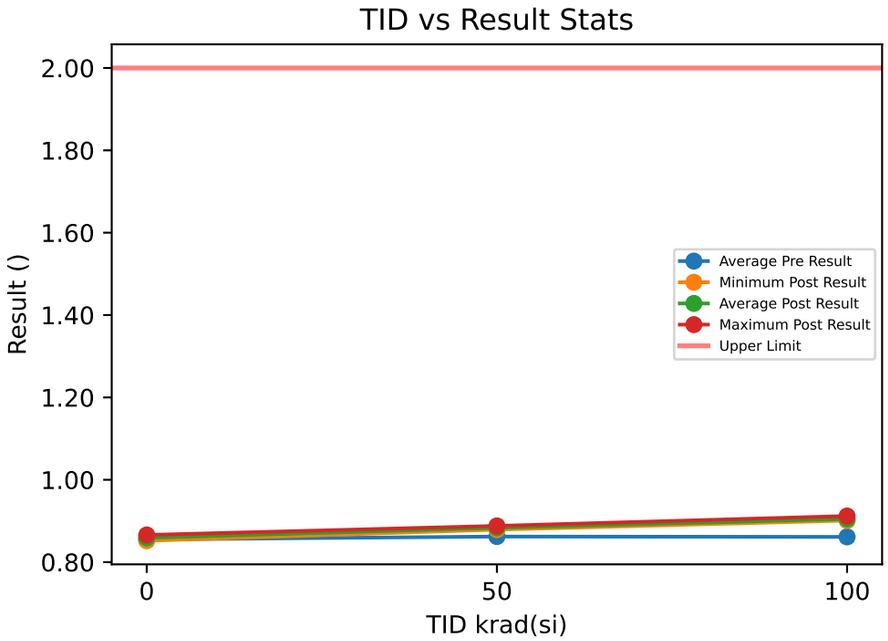
Test Results (Upper Limit = 2.0 ())

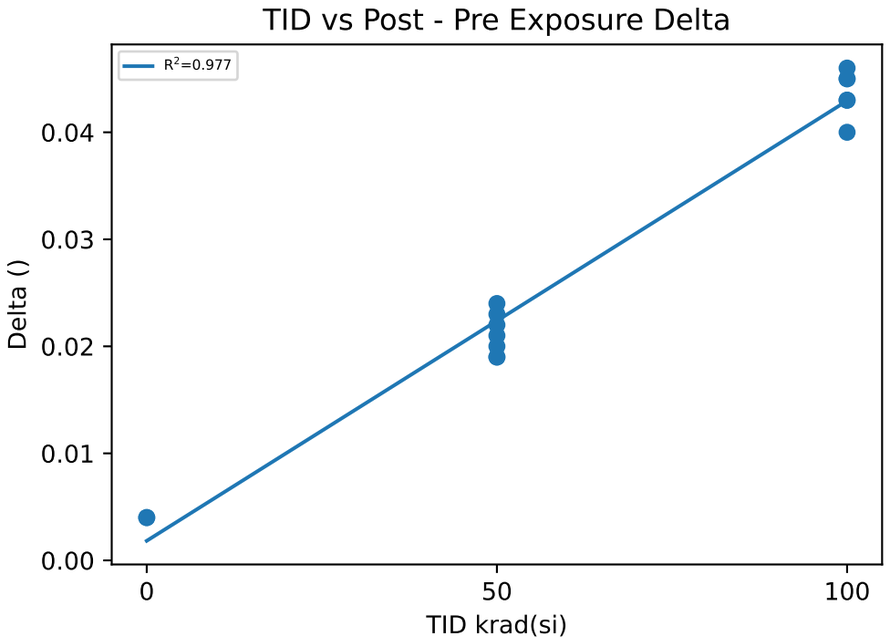
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.995	0.983	-0.012
89	50	Biased	0.991	0.981	-0.01
90	50	Biased	0.997	0.982	-0.015
92	50	Biased	1.001	0.986	-0.015
93	50	Unbiased	0.993	0.977	-0.016
94	50	Unbiased	1.006	0.987	-0.019
95	50	Unbiased	1.001	0.982	-0.019
96	100	Biased	0.997	0.974	-0.023
97	100	Biased	0.997	0.974	-0.023
98	100	Biased	0.992	0.967	-0.025
99	100	Unbiased	0.997	0.966	-0.031
100	100	Unbiased	0.99	0.959	-0.031
101	100	Unbiased	0.997	0.964	-0.033
102	0	Correlation	0.993	0.997	0.004
103	0	Correlation	0.986	0.989	0.003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.986	0.9895	0.993	0.0049497	0.989	0.993	0.997	0.0056569	0.003	0.0035	0.004	0.00070711
50	0.991	0.99771	1.006	0.0052509	0.977	0.98257	0.987	0.0033094	-0.019	-0.015143	-0.01	0.0033381
100	0.99	0.995	0.997	0.0031623	0.959	0.96733	0.974	0.0058538	-0.033	-0.027667	-0.023	0.0045019

Device Test: 5.109 PROPD_SR_UVLO(tpd_SR_UVLOB_SD/SR_UVLOB/7/3/0/0/0/@PROPD_SR_UVLO)





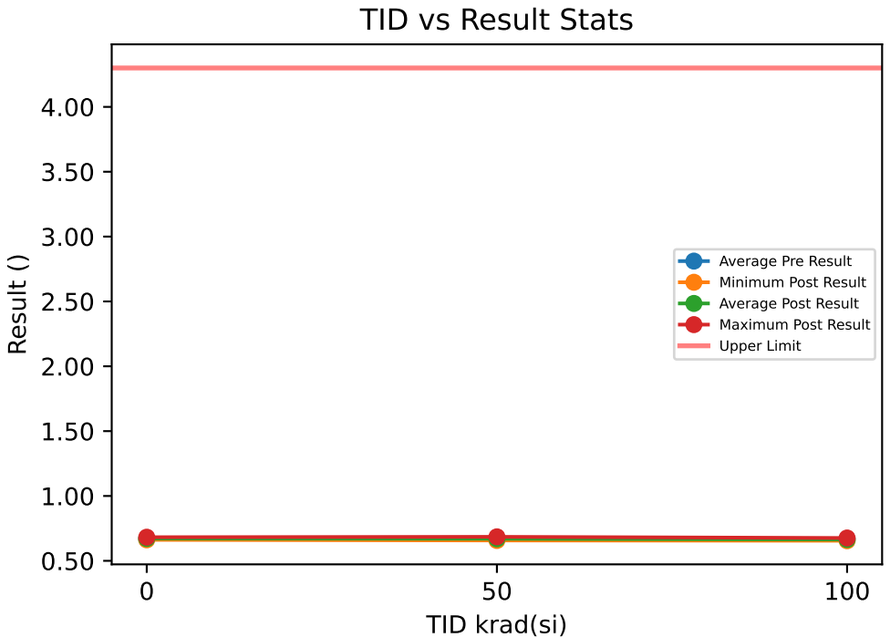
Test Results (Upper Limit = 2.0 ())

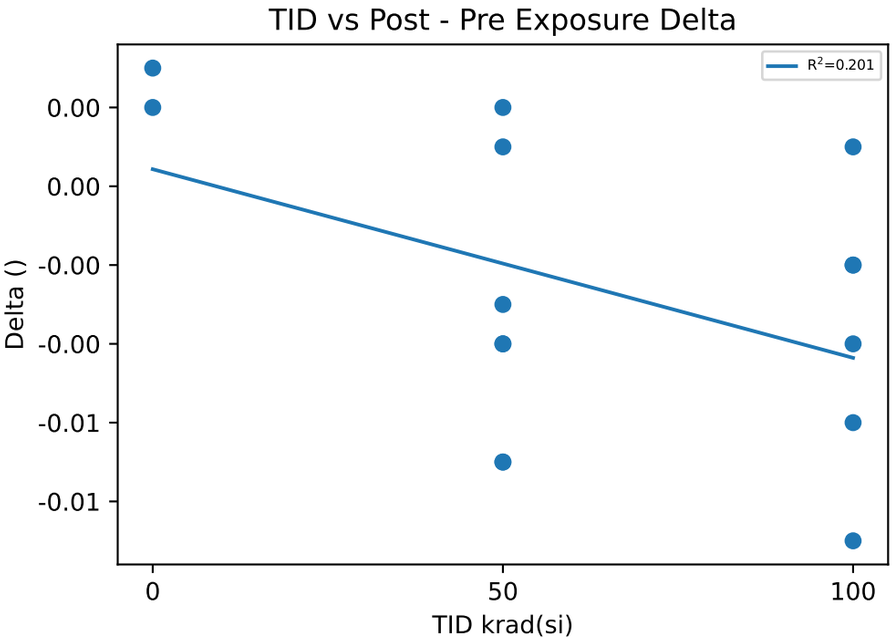
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.864	0.883	0.019
89	50	Biased	0.858	0.879	0.021
90	50	Biased	0.864	0.883	0.019
92	50	Biased	0.862	0.882	0.02
93	50	Unbiased	0.864	0.888	0.024
94	50	Unbiased	0.865	0.887	0.022
95	50	Unbiased	0.858	0.881	0.023
96	100	Biased	0.864	0.904	0.04
97	100	Biased	0.864	0.907	0.043
98	100	Biased	0.858	0.901	0.043
99	100	Unbiased	0.866	0.912	0.046
100	100	Unbiased	0.856	0.901	0.045
101	100	Unbiased	0.86	0.905	0.045
102	0	Correlation	0.862	0.866	0.004
103	0	Correlation	0.848	0.852	0.004

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.848	0.855	0.862	0.0098995	0.852	0.859	0.866	0.0098995	0.004	0.004	0.004	0
50	0.858	0.86214	0.865	0.0029681	0.879	0.88329	0.888	0.0031997	0.019	0.021143	0.024	0.0019518
100	0.856	0.86133	0.866	0.0039328	0.901	0.905	0.912	0.0041473	0.04	0.043667	0.046	0.0021602

Device Test: 5.11 PROPD_RESET(tpd_RESETB3_SU/RESETB3/7/3/0/0/0/@PROPD_RESET)





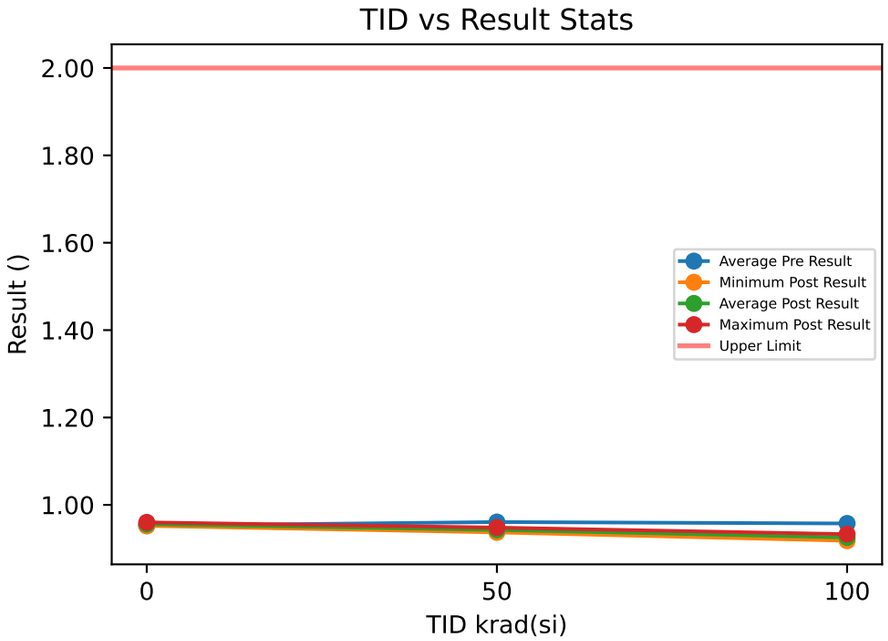
Test Results (Upper Limit = 4.3 ())

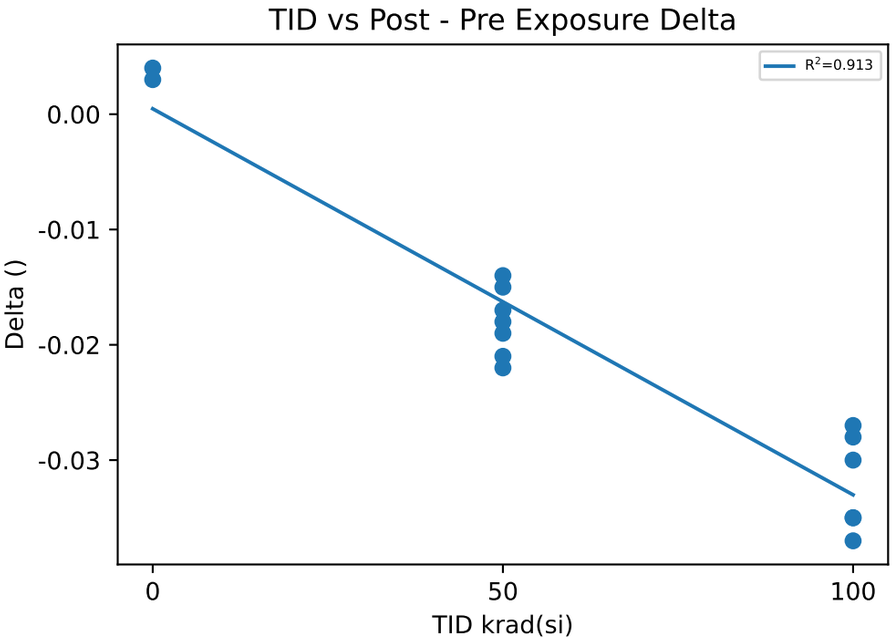
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.666	0.663	-0.003
89	50	Biased	0.675	0.671	-0.004
90	50	Biased	0.664	0.657	-0.007
92	50	Biased	0.661	0.662	0.001
93	50	Unbiased	0.683	0.685	0.002
94	50	Unbiased	0.678	0.671	-0.007
95	50	Unbiased	0.685	0.681	-0.004
96	100	Biased	0.657	0.655	-0.002
97	100	Biased	0.672	0.668	-0.004
98	100	Biased	0.675	0.666	-0.009
99	100	Unbiased	0.671	0.665	-0.006
100	100	Unbiased	0.678	0.676	-0.002
101	100	Unbiased	0.656	0.657	0.001
102	0	Correlation	0.679	0.682	0.003
103	0	Correlation	0.66	0.662	0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.66	0.6695	0.679	0.013435	0.662	0.672	0.682	0.014142	0.002	0.0025	0.003	0.00070711
50	0.661	0.67314	0.685	0.0095469	0.657	0.67	0.685	0.010247	-0.007	-0.0031429	0.002	0.0035322
100	0.656	0.66817	0.678	0.0093684	0.655	0.6645	0.676	0.0076616	-0.009	-0.0036667	0.001	0.0035024

Device Test: 5.110 PROPD_SR_UVLO(tpd_SR_UVLOB_SU/SR_UVLOB/7/14/0/0/0/@PROPD_SR_UVLO)





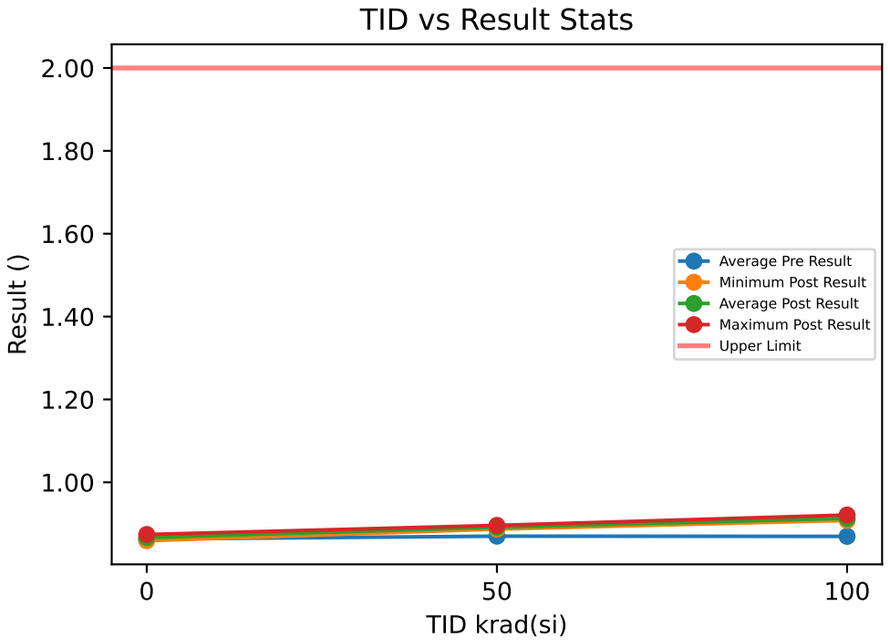
Test Results (Upper Limit = 2.0 ())

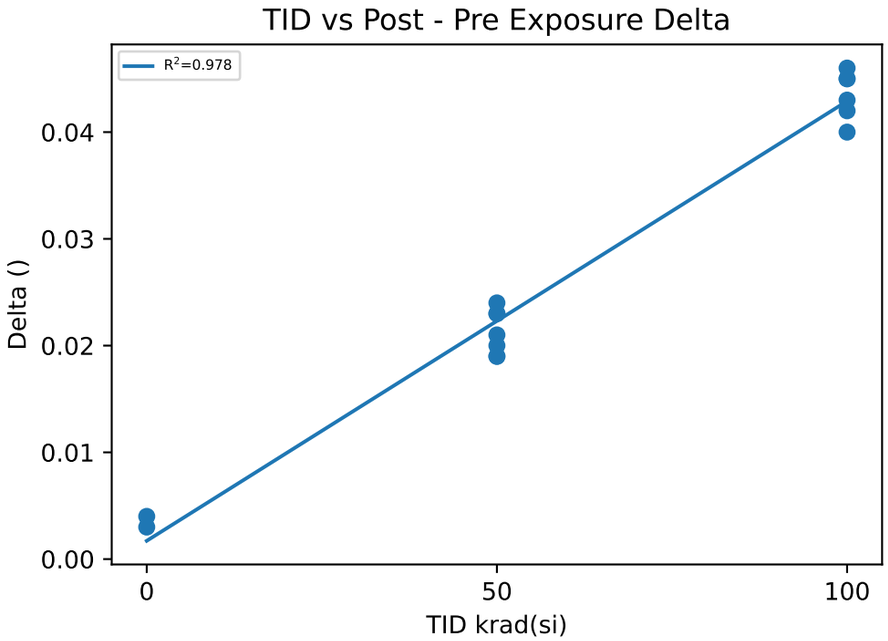
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.958	0.943	-0.015
89	50	Biased	0.956	0.942	-0.014
90	50	Biased	0.96	0.942	-0.018
92	50	Biased	0.963	0.946	-0.017
93	50	Unbiased	0.956	0.937	-0.019
94	50	Unbiased	0.969	0.948	-0.021
95	50	Unbiased	0.963	0.941	-0.022
96	100	Biased	0.96	0.933	-0.027
97	100	Biased	0.959	0.931	-0.028
98	100	Biased	0.955	0.925	-0.03
99	100	Unbiased	0.959	0.924	-0.035
100	100	Unbiased	0.953	0.918	-0.035
101	100	Unbiased	0.959	0.922	-0.037
102	0	Correlation	0.956	0.96	0.004
103	0	Correlation	0.949	0.952	0.003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.949	0.9525	0.956	0.0049497	0.952	0.956	0.96	0.0056569	0.003	0.0035	0.004	0.00070711
50	0.956	0.96071	0.969	0.0046803	0.937	0.94271	0.948	0.0035456	-0.022	-0.018	-0.014	0.0029439
100	0.953	0.9575	0.96	0.0028107	0.918	0.9255	0.933	0.0056125	-0.037	-0.032	-0.027	0.0041952

Device Test: 5.111 PROPD_SR_UVLO(tpd_SR_UVLOB_SD/SR_UVLOB/7/14/0/0/0/@PROPD_SR_UVLO)





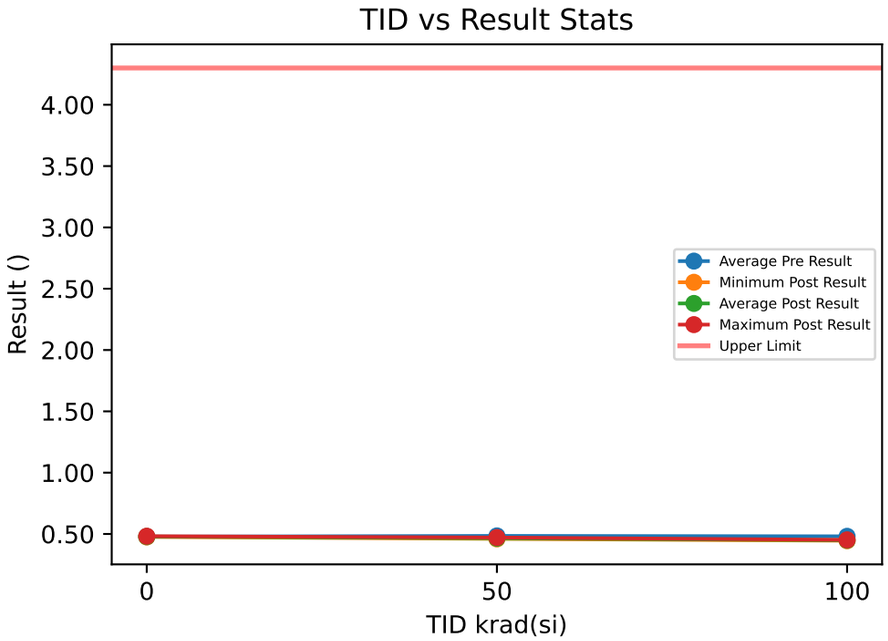
Test Results (Upper Limit = 2.0 ())

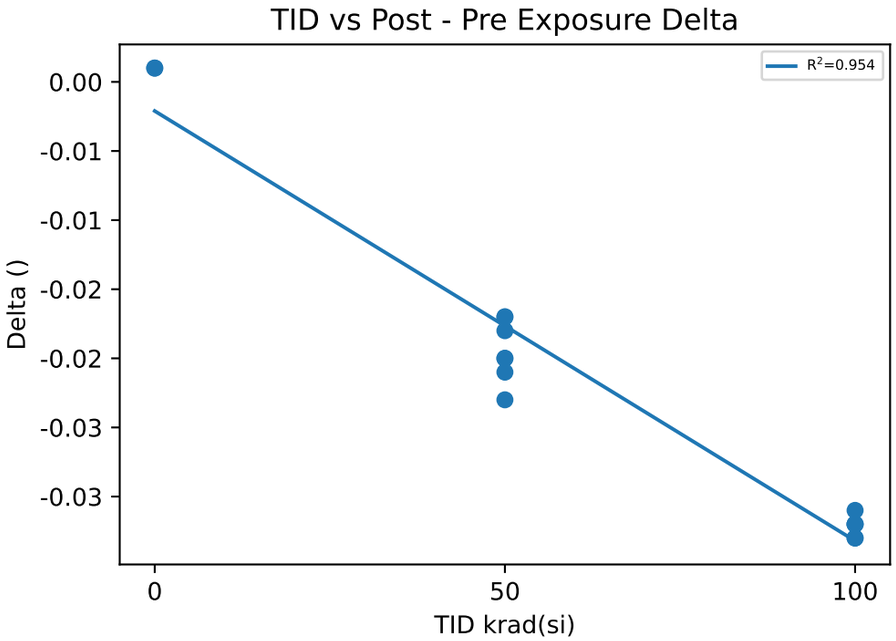
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.872	0.891	0.019
89	50	Biased	0.866	0.887	0.021
90	50	Biased	0.872	0.891	0.019
92	50	Biased	0.87	0.89	0.02
93	50	Unbiased	0.872	0.896	0.024
94	50	Unbiased	0.872	0.895	0.023
95	50	Unbiased	0.866	0.889	0.023
96	100	Biased	0.872	0.912	0.04
97	100	Biased	0.872	0.915	0.043
98	100	Biased	0.866	0.908	0.042
99	100	Unbiased	0.875	0.921	0.046
100	100	Unbiased	0.864	0.909	0.045
101	100	Unbiased	0.868	0.913	0.045
102	0	Correlation	0.87	0.874	0.004
103	0	Correlation	0.856	0.859	0.003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.856	0.863	0.87	0.0098995	0.859	0.8665	0.874	0.010607	0.003	0.0035	0.004	0.00070711
50	0.866	0.87	0.872	0.0028284	0.887	0.89129	0.896	0.0031997	0.019	0.021286	0.024	0.0020587
100	0.864	0.8695	0.875	0.0041833	0.908	0.913	0.921	0.0046904	0.04	0.0435	0.046	0.0022583

Device Test: 5.12 PROPD_PWRGD(tpd_PWRGD_SU/PWRGD/7/3/0/0/0/@PROPD_PWRGD)





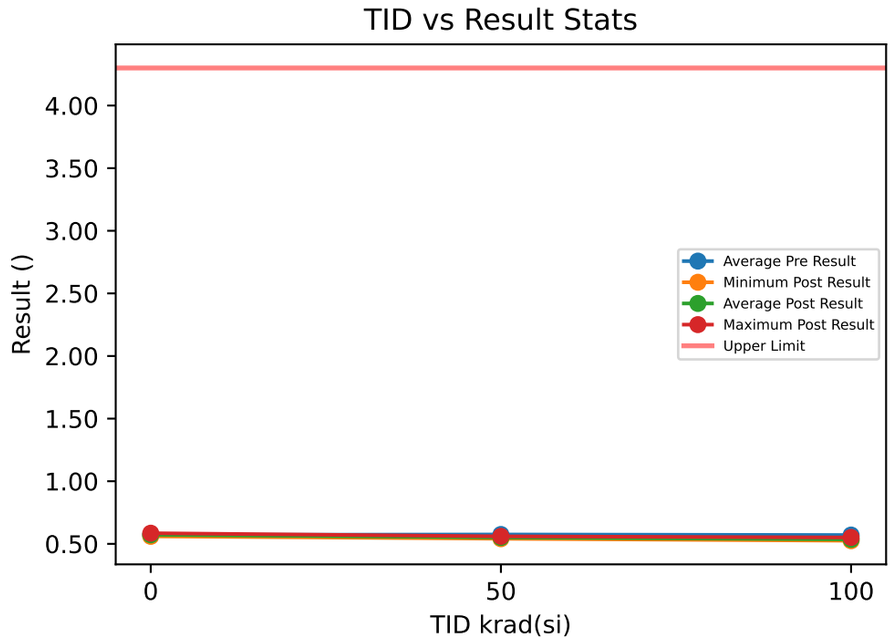
Test Results (Upper Limit = 4.3 ())

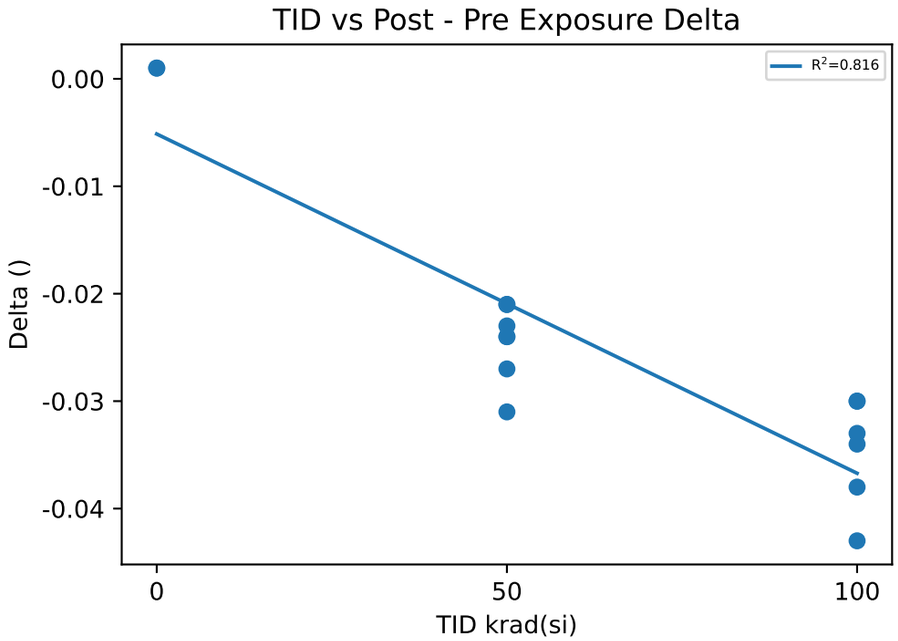
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.483	0.463	-0.02
89	50	Biased	0.485	0.467	-0.018
90	50	Biased	0.48	0.46	-0.02
92	50	Biased	0.488	0.471	-0.017
93	50	Unbiased	0.485	0.468	-0.017
94	50	Unbiased	0.485	0.462	-0.023
95	50	Unbiased	0.485	0.464	-0.021
96	100	Biased	0.482	0.45	-0.032
97	100	Biased	0.48	0.448	-0.032
98	100	Biased	0.478	0.445	-0.033
99	100	Unbiased	0.482	0.451	-0.031
100	100	Unbiased	0.485	0.452	-0.033
101	100	Unbiased	0.479	0.447	-0.032
102	0	Correlation	0.475	0.476	0.001
103	0	Correlation	0.481	0.482	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.475	0.478	0.481	0.0042426	0.476	0.479	0.482	0.0042426	0.001	0.001	0.001	0
50	0.48	0.48443	0.488	0.0024398	0.46	0.465	0.471	0.0038297	-0.023	-0.019429	-0.017	0.0022254
100	0.478	0.481	0.485	0.0025298	0.445	0.44883	0.452	0.0026394	-0.033	-0.032167	-0.031	0.00075277

Device Test: 5.13 PROPD_RESET(tpd_RESETB2_SD/RESETB2/7/3/0/0/0/@PROPD_RESET)





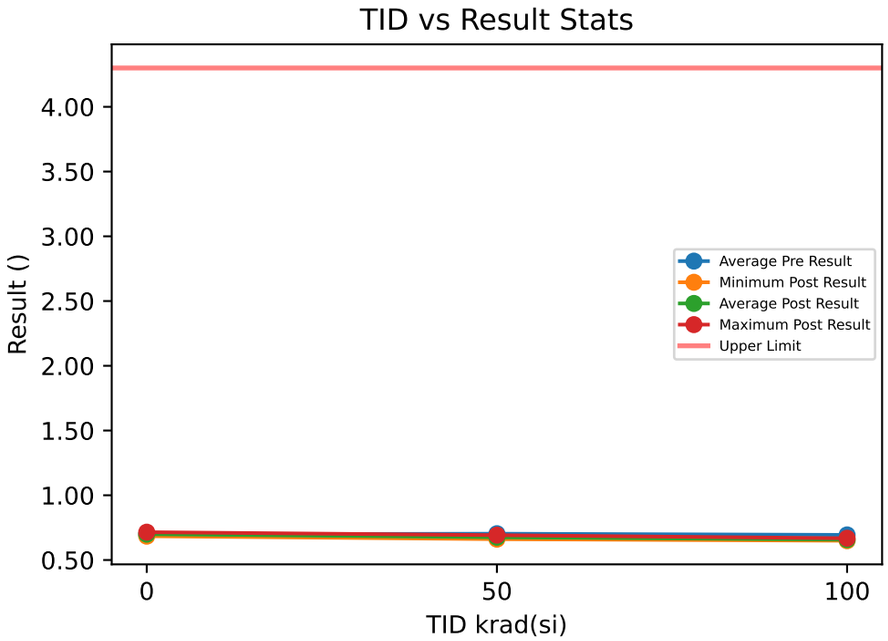
Test Results (Upper Limit = 4.3 ())

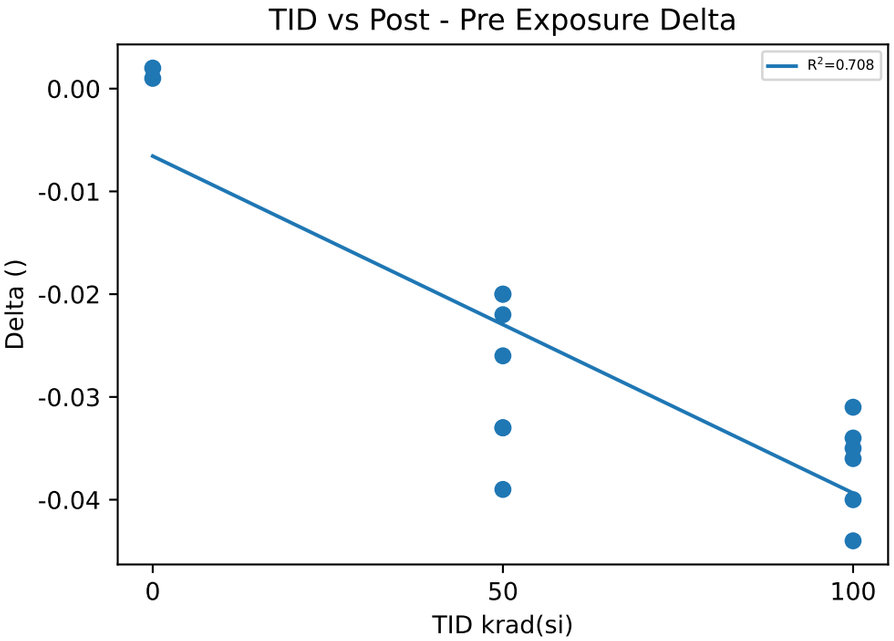
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.587	0.56	-0.027
89	50	Biased	0.569	0.548	-0.021
90	50	Biased	0.562	0.541	-0.021
92	50	Biased	0.569	0.545	-0.024
93	50	Unbiased	0.57	0.547	-0.023
94	50	Unbiased	0.584	0.553	-0.031
95	50	Unbiased	0.583	0.559	-0.024
96	100	Biased	0.565	0.527	-0.038
97	100	Biased	0.568	0.525	-0.043
98	100	Biased	0.563	0.533	-0.03
99	100	Unbiased	0.571	0.537	-0.034
100	100	Unbiased	0.581	0.551	-0.03
101	100	Unbiased	0.574	0.541	-0.033
102	0	Correlation	0.559	0.56	0.001
103	0	Correlation	0.584	0.585	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.559	0.5715	0.584	0.017678	0.56	0.5725	0.585	0.017678	0.001	0.001	0.001	0
50	0.562	0.57486	0.587	0.0096165	0.541	0.55043	0.56	0.0071614	-0.031	-0.024429	-0.021	0.0035523
100	0.563	0.57033	0.581	0.0065625	0.525	0.53567	0.551	0.0096056	-0.043	-0.034667	-0.03	0.0050465

Device Test: 5.14 PROPD_RESET(tpd_RESETB4_SD/RESETB4/7/3/0/0/0/@PROPD_RESET)





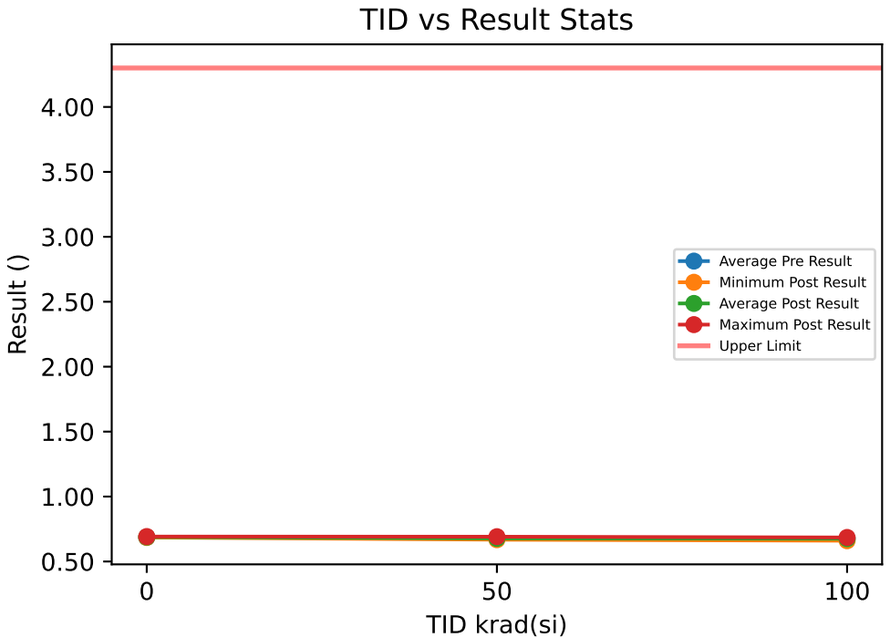
Test Results (Upper Limit = 4.3 ())

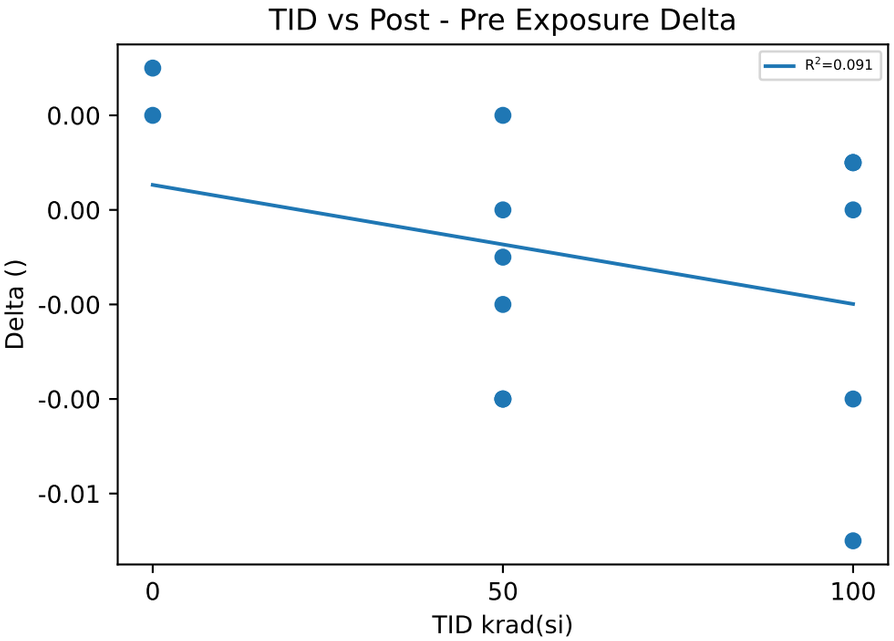
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.707	0.674	-0.033
89	50	Biased	0.696	0.674	-0.022
90	50	Biased	0.693	0.667	-0.026
92	50	Biased	0.712	0.692	-0.02
93	50	Unbiased	0.711	0.691	-0.02
94	50	Unbiased	0.7	0.661	-0.039
95	50	Unbiased	0.703	0.67	-0.033
96	100	Biased	0.685	0.65	-0.035
97	100	Biased	0.694	0.663	-0.031
98	100	Biased	0.685	0.649	-0.036
99	100	Unbiased	0.695	0.661	-0.034
100	100	Unbiased	0.712	0.668	-0.044
101	100	Unbiased	0.693	0.653	-0.04
102	0	Correlation	0.683	0.684	0.001
103	0	Correlation	0.713	0.715	0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.683	0.698	0.713	0.021213	0.684	0.6995	0.715	0.02192	0.001	0.0015	0.002	0.00070711
50	0.693	0.70314	0.712	0.0072899	0.661	0.67557	0.692	0.011759	-0.039	-0.027571	-0.02	0.0075024
100	0.685	0.694	0.712	0.0098793	0.649	0.65733	0.668	0.0077632	-0.044	-0.036667	-0.031	0.0046332

Device Test: 5.15 PROPD_RESET(tpd_RESETB1_SU/RESETB1/7/14/0/0/0/@PROPD_RESET)





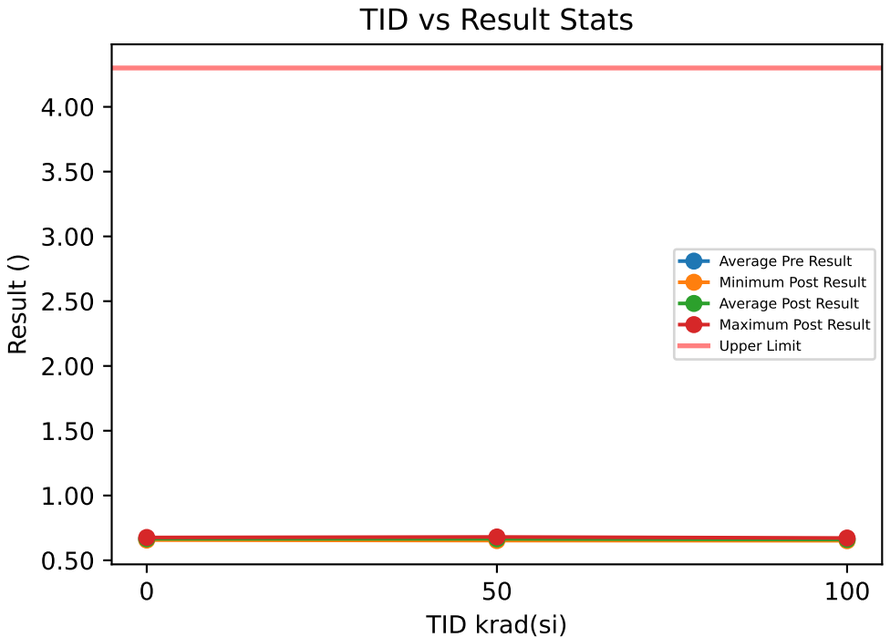
Test Results (Upper Limit = 4.3 ())

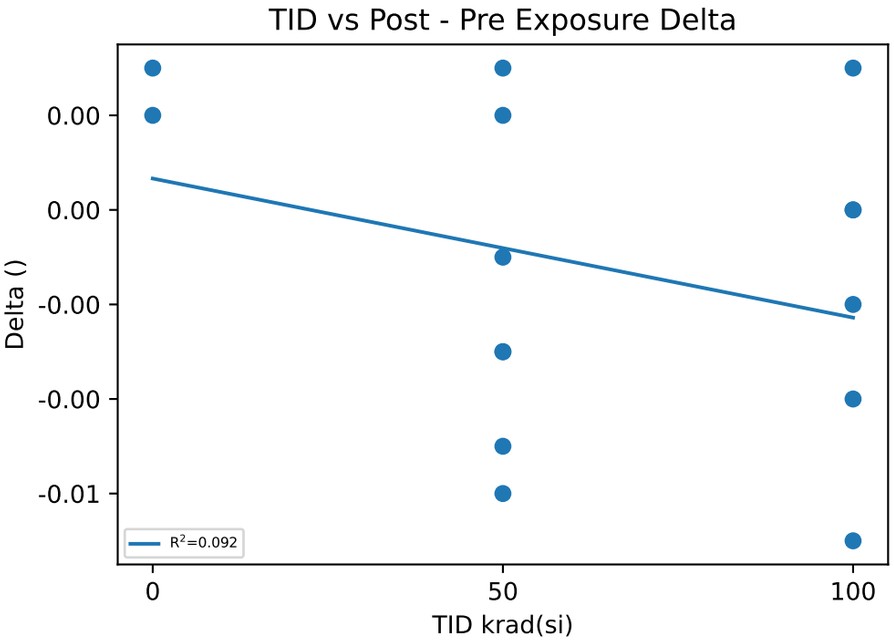
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.677	0.677	0
89	50	Biased	0.671	0.669	-0.002
90	50	Biased	0.669	0.668	-0.001
92	50	Biased	0.67	0.672	0.002
93	50	Unbiased	0.689	0.685	-0.004
94	50	Unbiased	0.695	0.691	-0.004
95	50	Unbiased	0.686	0.682	-0.004
96	100	Biased	0.668	0.668	0
97	100	Biased	0.684	0.685	0.001
98	100	Biased	0.677	0.678	0.001
99	100	Unbiased	0.681	0.682	0.001
100	100	Unbiased	0.685	0.681	-0.004
101	100	Unbiased	0.667	0.66	-0.007
102	0	Correlation	0.683	0.685	0.002
103	0	Correlation	0.689	0.692	0.003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.683	0.686	0.689	0.0042426	0.685	0.6885	0.692	0.0049497	0.002	0.0025	0.003	0.00070711
50	0.669	0.67957	0.695	0.010422	0.668	0.67771	0.691	0.008674	-0.004	-0.0018571	0.002	0.0023401
100	0.667	0.677	0.685	0.007874	0.66	0.67567	0.685	0.0096471	-0.007	-0.0013333	0.001	0.0033862

Device Test: 5.16 PROPD_RESET(tpd_RESETB3_SU/RESETB3/7/14/0/0/0/@PROPD_RESET)





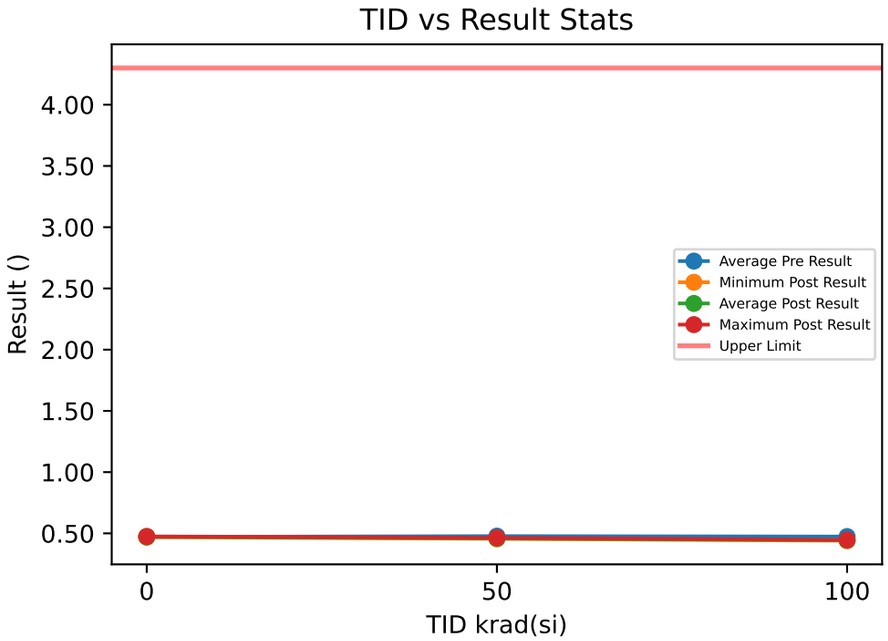
Test Results (Upper Limit = 4.3 ())

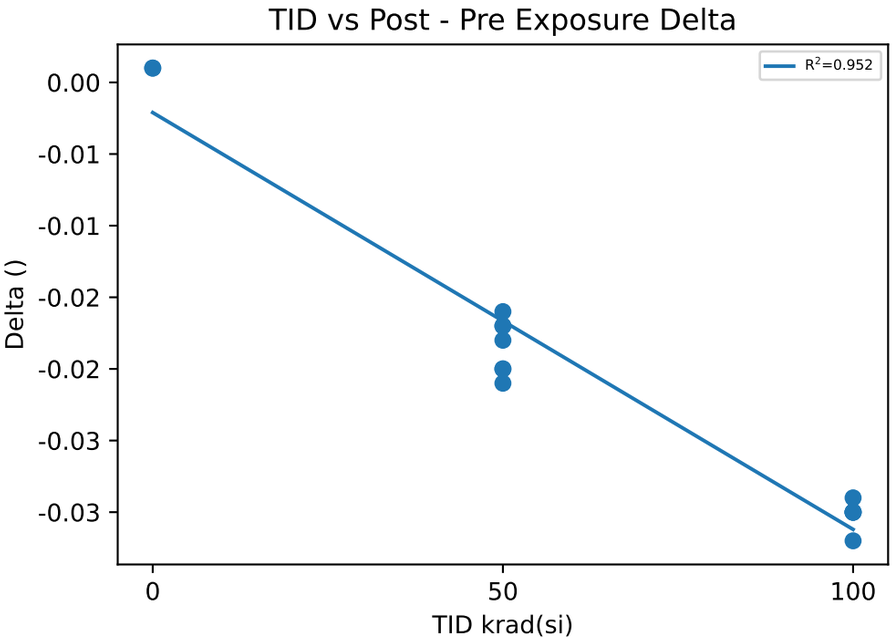
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.66	0.659	-0.001
89	50	Biased	0.67	0.667	-0.003
90	50	Biased	0.657	0.652	-0.005
92	50	Biased	0.655	0.657	0.002
93	50	Unbiased	0.677	0.68	0.003
94	50	Unbiased	0.672	0.666	-0.006
95	50	Unbiased	0.68	0.677	-0.003
96	100	Biased	0.651	0.651	0
97	100	Biased	0.666	0.664	-0.002
98	100	Biased	0.669	0.662	-0.007
99	100	Unbiased	0.665	0.661	-0.004
100	100	Unbiased	0.672	0.672	0
101	100	Unbiased	0.65	0.653	0.003
102	0	Correlation	0.673	0.676	0.003
103	0	Correlation	0.654	0.656	0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.654	0.6635	0.673	0.013435	0.656	0.666	0.676	0.014142	0.002	0.0025	0.003	0.00070711
50	0.655	0.66729	0.68	0.0099618	0.652	0.66543	0.68	0.010342	-0.006	-0.0018571	0.003	0.0033877
100	0.65	0.66217	0.672	0.0093684	0.651	0.6605	0.672	0.0076616	-0.007	-0.0016667	0.003	0.0035024

Device Test: 5.17 PROPD_PWRGD(tpd_PWRGD_SU/PWRGD/7/14/0/0/0/@PROPD_PWRGD)





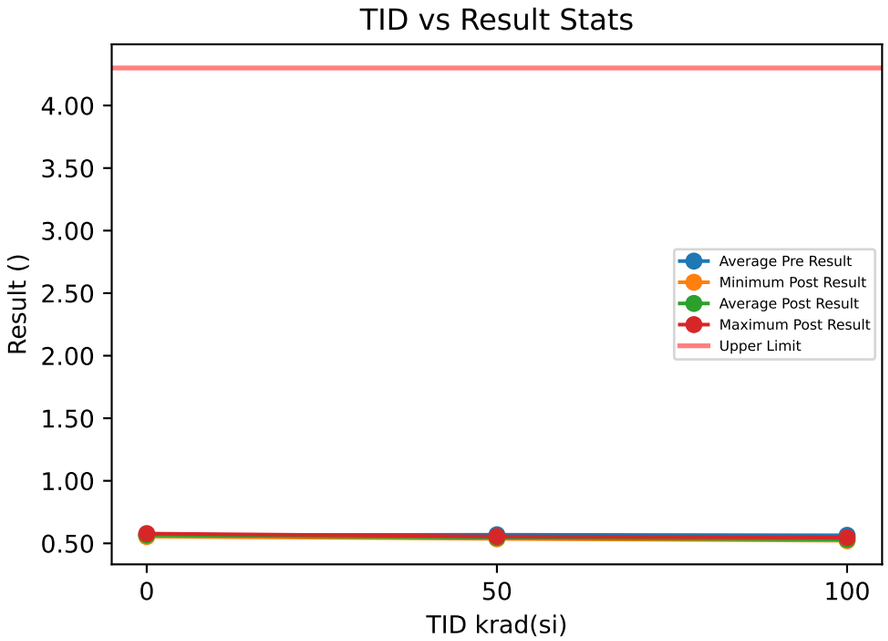
Test Results (Upper Limit = 4.3 ())

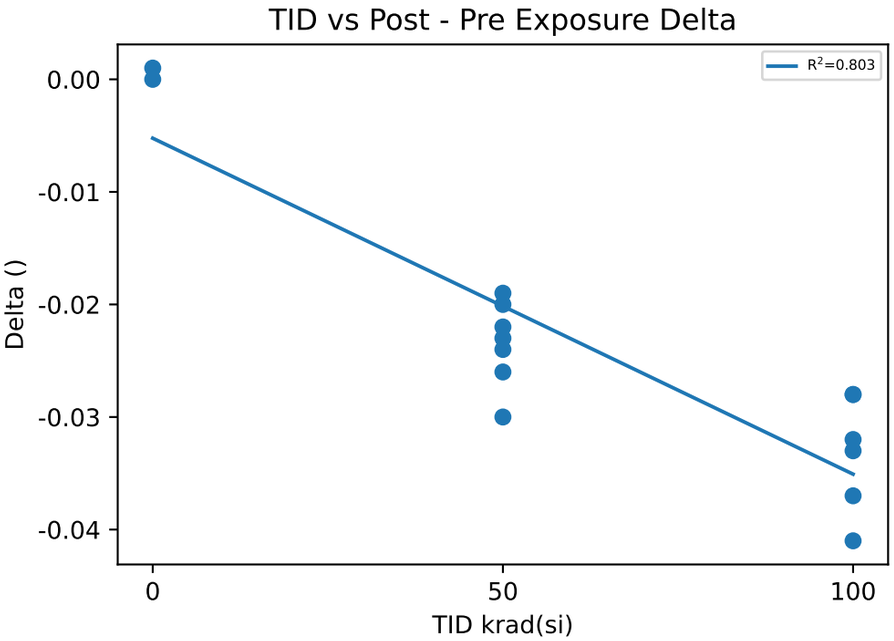
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.476	0.456	-0.02
89	50	Biased	0.478	0.461	-0.017
90	50	Biased	0.473	0.455	-0.018
92	50	Biased	0.481	0.464	-0.017
93	50	Unbiased	0.478	0.462	-0.016
94	50	Unbiased	0.478	0.457	-0.021
95	50	Unbiased	0.478	0.458	-0.02
96	100	Biased	0.475	0.445	-0.03
97	100	Biased	0.473	0.443	-0.03
98	100	Biased	0.47	0.44	-0.03
99	100	Unbiased	0.475	0.446	-0.029
100	100	Unbiased	0.479	0.447	-0.032
101	100	Unbiased	0.472	0.442	-0.03
102	0	Correlation	0.468	0.469	0.001
103	0	Correlation	0.474	0.475	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.468	0.471	0.474	0.0042426	0.469	0.472	0.475	0.0042426	0.001	0.001	0.001	3.9252e-17
50	0.473	0.47743	0.481	0.0024398	0.455	0.459	0.464	0.0033665	-0.021	-0.018429	-0.016	0.0019024
100	0.47	0.474	0.479	0.0030984	0.44	0.44383	0.447	0.0026394	-0.032	-0.030167	-0.029	0.00098319

Device Test: 5.18 PROPD_RESET(tpd_RESETB2_SD/RESETB2/7/14/0/0/0/@PROPD_RESET)





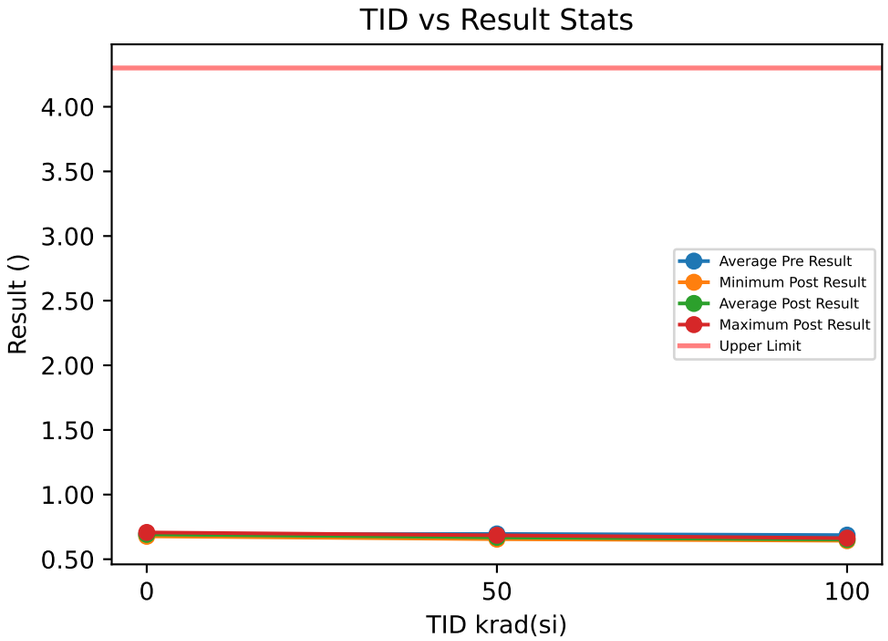
Test Results (Upper Limit = 4.3 ())

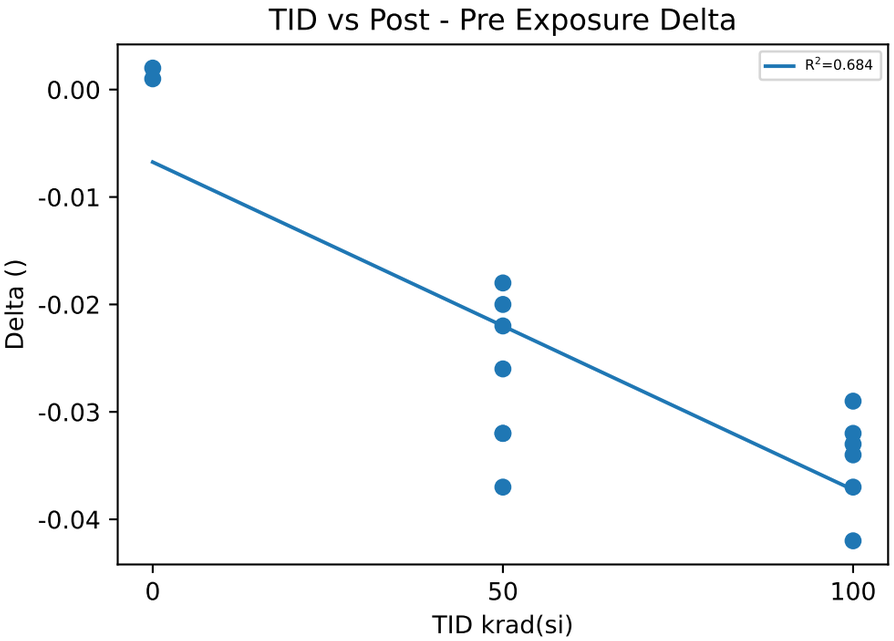
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.581	0.555	-0.026
89	50	Biased	0.562	0.543	-0.019
90	50	Biased	0.556	0.536	-0.02
92	50	Biased	0.563	0.54	-0.023
93	50	Unbiased	0.564	0.542	-0.022
94	50	Unbiased	0.578	0.548	-0.03
95	50	Unbiased	0.577	0.553	-0.024
96	100	Biased	0.56	0.523	-0.037
97	100	Biased	0.562	0.521	-0.041
98	100	Biased	0.556	0.528	-0.028
99	100	Unbiased	0.565	0.532	-0.033
100	100	Unbiased	0.574	0.546	-0.028
101	100	Unbiased	0.568	0.536	-0.032
102	0	Correlation	0.553	0.554	0.001
103	0	Correlation	0.578	0.578	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.553	0.5655	0.578	0.017678	0.554	0.566	0.578	0.016971	0	0.0005	0.001	0.00070711
50	0.556	0.56871	0.581	0.0097248	0.536	0.54529	0.555	0.0069693	-0.03	-0.023429	-0.019	0.0037353
100	0.556	0.56417	0.574	0.0063377	0.521	0.531	0.546	0.0092087	-0.041	-0.033167	-0.028	0.0051153

Device Test: 5.19 PROPD_RESET(tpd_RESETB4_SD/RESETB4/7/14/0/0/0/@PROPD_RESET)





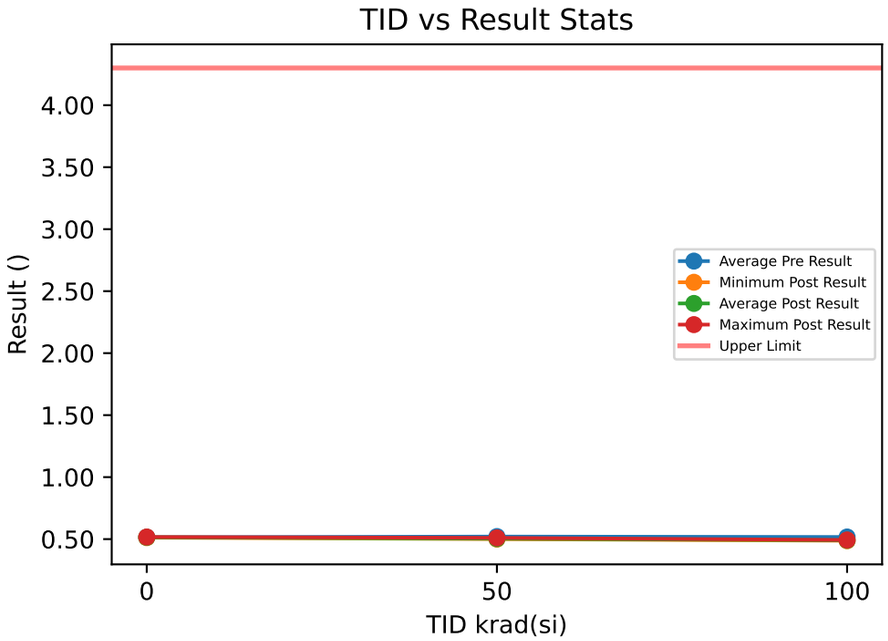
Test Results (Upper Limit = 4.3 ())

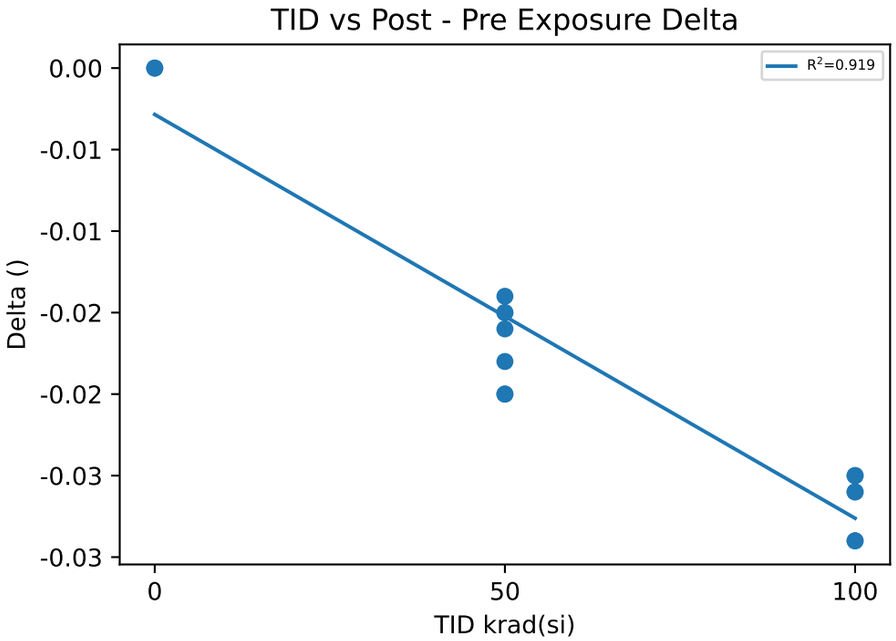
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.699	0.667	-0.032
89	50	Biased	0.689	0.667	-0.022
90	50	Biased	0.686	0.66	-0.026
92	50	Biased	0.704	0.684	-0.02
93	50	Unbiased	0.703	0.685	-0.018
94	50	Unbiased	0.692	0.655	-0.037
95	50	Unbiased	0.696	0.664	-0.032
96	100	Biased	0.678	0.645	-0.033
97	100	Biased	0.686	0.657	-0.029
98	100	Biased	0.677	0.643	-0.034
99	100	Unbiased	0.688	0.656	-0.032
100	100	Unbiased	0.705	0.663	-0.042
101	100	Unbiased	0.685	0.648	-0.037
102	0	Correlation	0.676	0.677	0.001
103	0	Correlation	0.705	0.707	0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.676	0.6905	0.705	0.020506	0.677	0.692	0.707	0.021213	0.001	0.0015	0.002	0.00070711
50	0.686	0.69557	0.704	0.0069007	0.655	0.66886	0.685	0.011481	-0.037	-0.026714	-0.018	0.0071348
100	0.677	0.6865	0.705	0.010095	0.643	0.652	0.663	0.0078486	-0.042	-0.0345	-0.029	0.0045056

Device Test: 5.2 PROPD_PWRGD(tpd_PWRGD_SU/PWRGD/1.6/3/0/0/0/@PROPD_PWRGD)





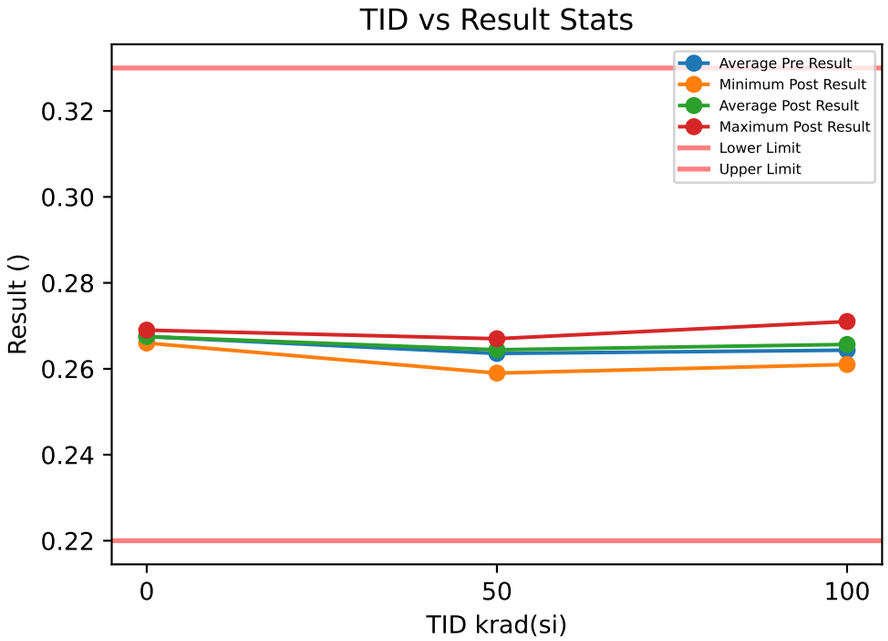
Test Results (Upper Limit = 4.3 ())

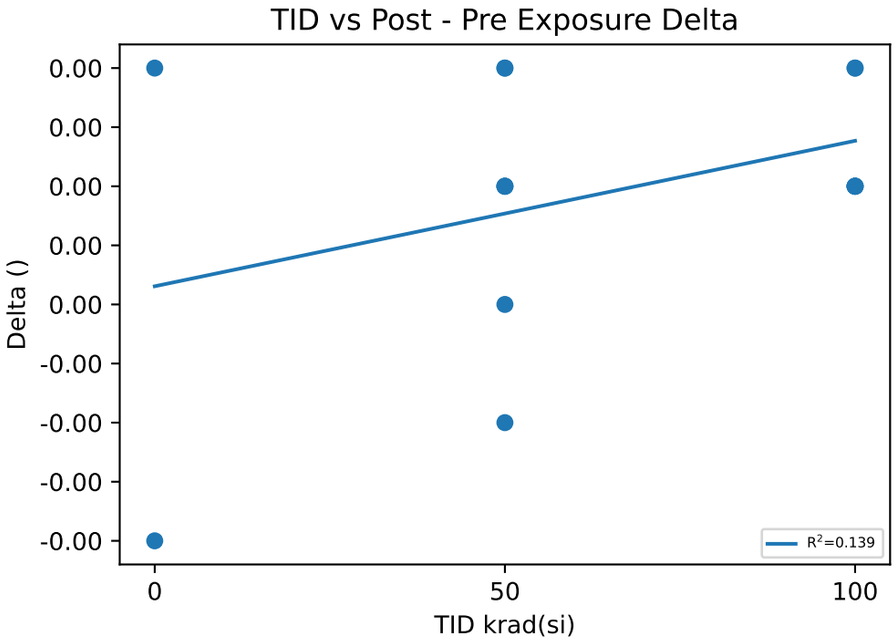
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.519	0.501	-0.018
89	50	Biased	0.52	0.506	-0.014
90	50	Biased	0.516	0.5	-0.016
92	50	Biased	0.525	0.51	-0.015
93	50	Unbiased	0.521	0.506	-0.015
94	50	Unbiased	0.52	0.5	-0.02
95	50	Unbiased	0.522	0.502	-0.02
96	100	Biased	0.517	0.491	-0.026
97	100	Biased	0.516	0.491	-0.025
98	100	Biased	0.513	0.488	-0.025
99	100	Unbiased	0.518	0.492	-0.026
100	100	Unbiased	0.522	0.493	-0.029
101	100	Unbiased	0.516	0.487	-0.029
102	0	Correlation	0.512	0.512	0
103	0	Correlation	0.517	0.517	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.512	0.5145	0.517	0.0035355	0.512	0.5145	0.517	0.0035355	0	0	0	0
50	0.516	0.52043	0.525	0.0027603	0.5	0.50357	0.51	0.0038235	-0.02	-0.016857	-0.014	0.0024785
100	0.513	0.517	0.522	0.0029665	0.487	0.49033	0.493	0.0023381	-0.029	-0.026667	-0.025	0.0018619

Device Test: 5.20 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB1_SU/RESETB1/1.6/3/10.5K/0/0/@DLY_TMR_10KOHM)





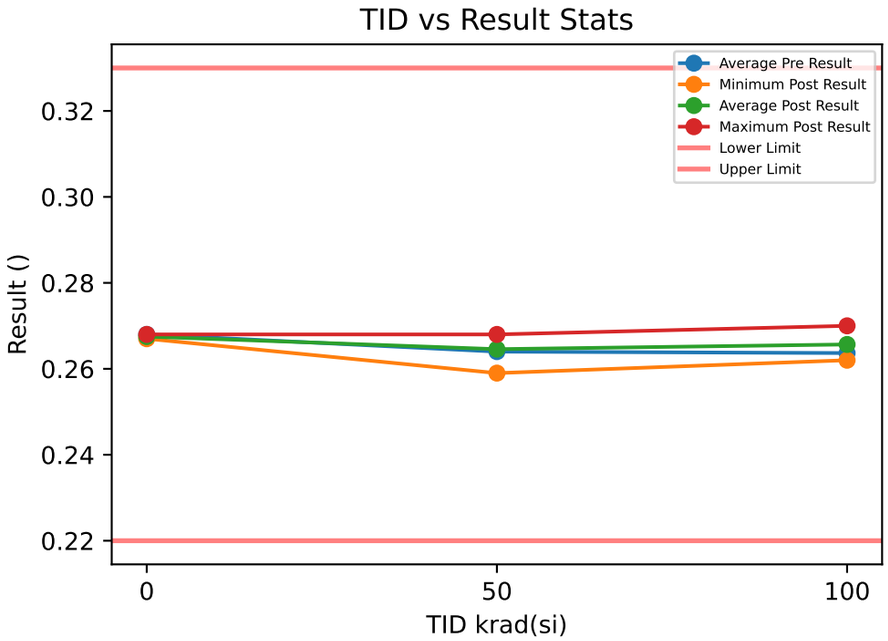
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

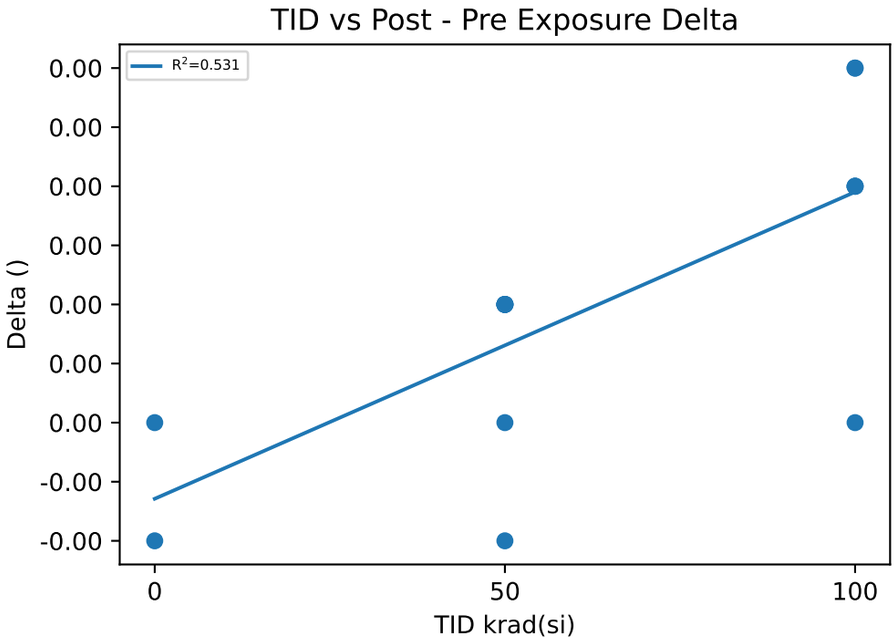
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.266	0.267	0.001
89	50	Biased	0.266	0.265	-0.001
90	50	Biased	0.258	0.259	0.001
92	50	Biased	0.266	0.266	0
93	50	Unbiased	0.258	0.26	0.002
94	50	Unbiased	0.266	0.267	0.001
95	50	Unbiased	0.265	0.267	0.002
96	100	Biased	0.26	0.261	0.001
97	100	Biased	0.269	0.271	0.002
98	100	Biased	0.267	0.268	0.001
99	100	Unbiased	0.262	0.263	0.001
100	100	Unbiased	0.26	0.262	0.002
101	100	Unbiased	0.268	0.269	0.001
102	0	Correlation	0.267	0.269	0.002
103	0	Correlation	0.268	0.266	-0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.267	0.2675	0.268	0.00070711	0.266	0.2675	0.269	0.0021213	-0.002	0	0.002	0.0028284
50	0.258	0.26357	0.266	0.0038235	0.259	0.26443	0.267	0.0034572	-0.001	0.00085714	0.002	0.001069
100	0.26	0.26433	0.269	0.0041312	0.261	0.26567	0.271	0.0041793	0.001	0.0013333	0.002	0.0005164

Device Test: 5.21 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB3_SU/RESETB3/1.6/3/10.5K/0/0/@DLY_TMR_10KOHM)





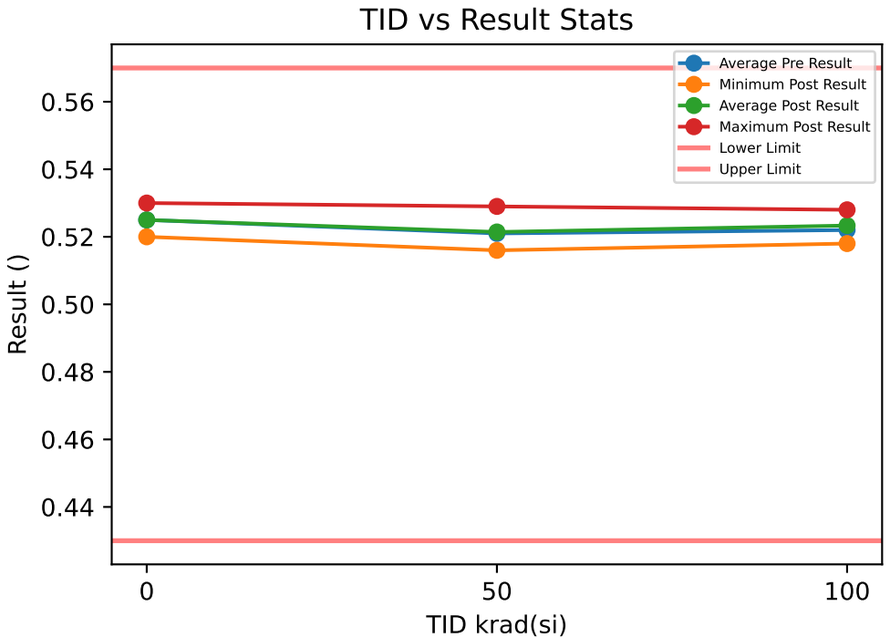
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

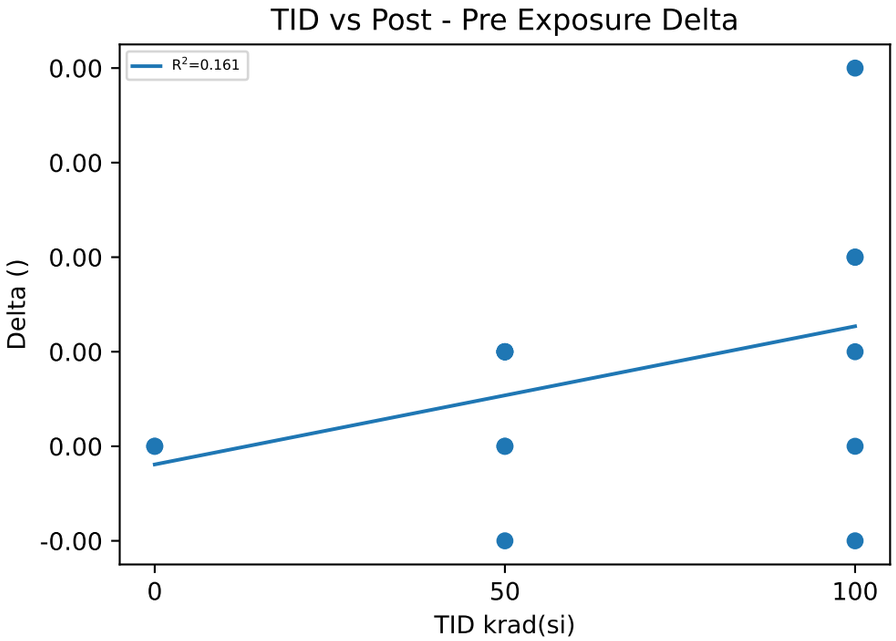
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.266	0.267	0.001
89	50	Biased	0.265	0.266	0.001
90	50	Biased	0.258	0.259	0.001
92	50	Biased	0.266	0.266	0
93	50	Unbiased	0.26	0.259	-0.001
94	50	Unbiased	0.267	0.268	0.001
95	50	Unbiased	0.266	0.267	0.001
96	100	Biased	0.262	0.262	0
97	100	Biased	0.268	0.27	0.002
98	100	Biased	0.266	0.268	0.002
99	100	Unbiased	0.26	0.263	0.003
100	100	Unbiased	0.26	0.262	0.002
101	100	Unbiased	0.266	0.269	0.003
102	0	Correlation	0.268	0.268	0
103	0	Correlation	0.268	0.267	-0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.268	0.268	0.268	0	0.267	0.2675	0.268	0.00070711	-0.001	-0.0005	0	0.00070711
50	0.258	0.264	0.267	0.0035119	0.259	0.26457	0.268	0.0038668	-0.001	0.00057143	0.001	0.0007868
100	0.26	0.26367	0.268	0.0034448	0.262	0.26567	0.27	0.0037238	0	0.002	0.003	0.0010954

Device Test: 5.22 WD_TMR_10KOHM(twd_Res10p5K_WDOB_SU/WDOB/1.6/3/10.5K/0/0/@WD_TMR_10KOHM)





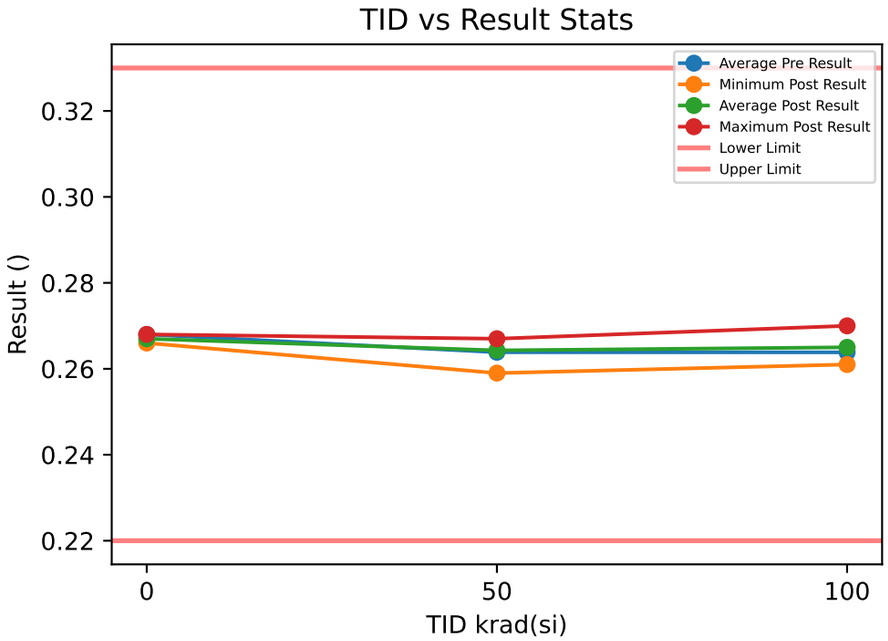
Test Results (Lower Limit = 0.43, Upper Limit = 0.57 ())

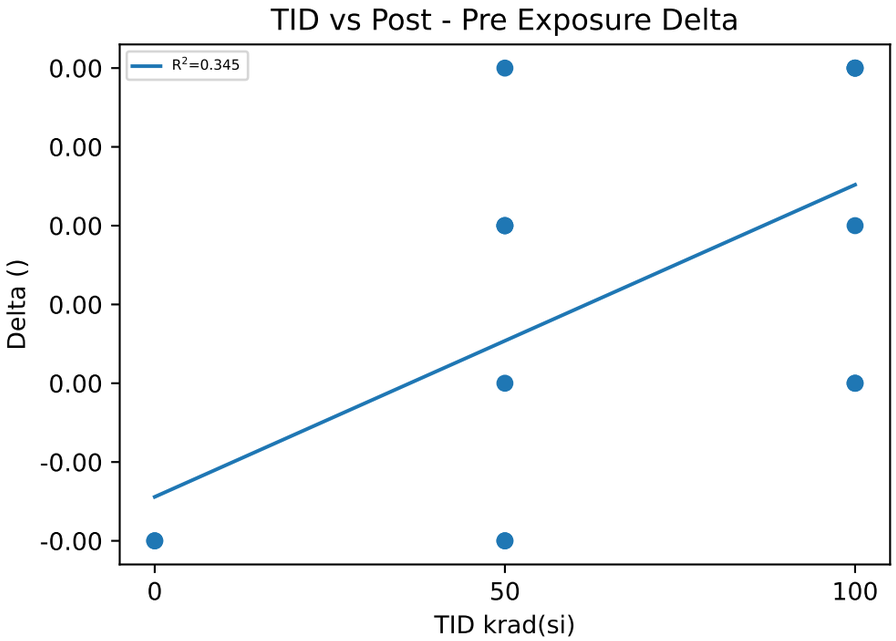
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.522	0.521	-0.001
89	50	Biased	0.515	0.516	0.001
90	50	Biased	0.517	0.518	0.001
92	50	Biased	0.524	0.525	0.001
93	50	Unbiased	0.517	0.518	0.001
94	50	Unbiased	0.529	0.529	0
95	50	Unbiased	0.523	0.523	0
96	100	Biased	0.521	0.52	-0.001
97	100	Biased	0.525	0.526	0.001
98	100	Biased	0.518	0.518	0
99	100	Unbiased	0.524	0.528	0.004
100	100	Unbiased	0.52	0.522	0.002
101	100	Unbiased	0.524	0.526	0.002
102	0	Correlation	0.53	0.53	0
103	0	Correlation	0.52	0.52	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.52	0.525	0.53	0.0070711	0.52	0.525	0.53	0.0070711	0	0	0	0
50	0.515	0.521	0.529	0.0049329	0.516	0.52143	0.529	0.0045774	-0.001	0.00042857	0.001	0.0007868
100	0.518	0.522	0.525	0.0027568	0.518	0.52333	0.528	0.0039328	-0.001	0.0013333	0.004	0.0017512

Device Test: 5.23 DLY_TMR_10KOHM(tdly_Res10p5K_PWRGD_SU/PWRGD/1.6/3/10.5K/0/0/@DLY_TMR_10KOHM)





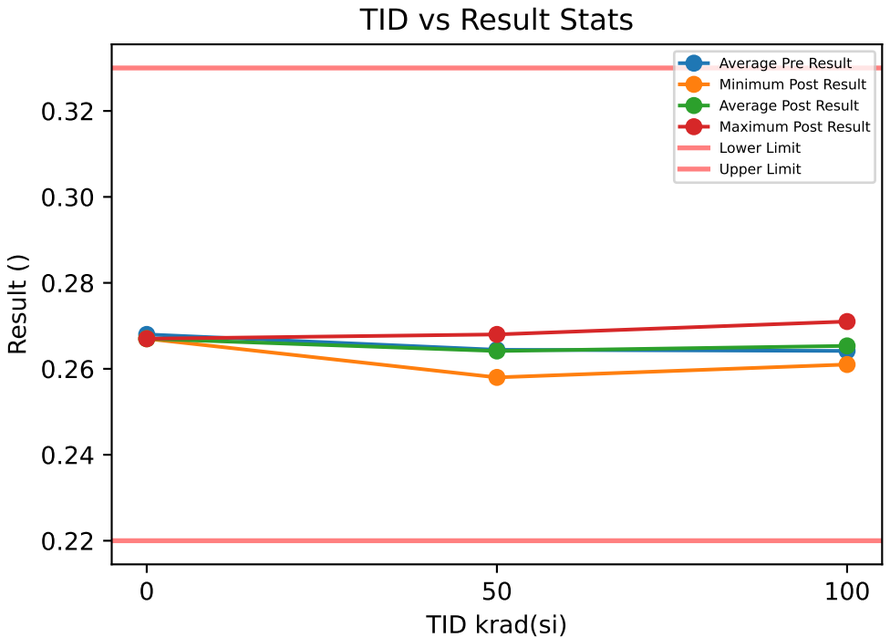
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

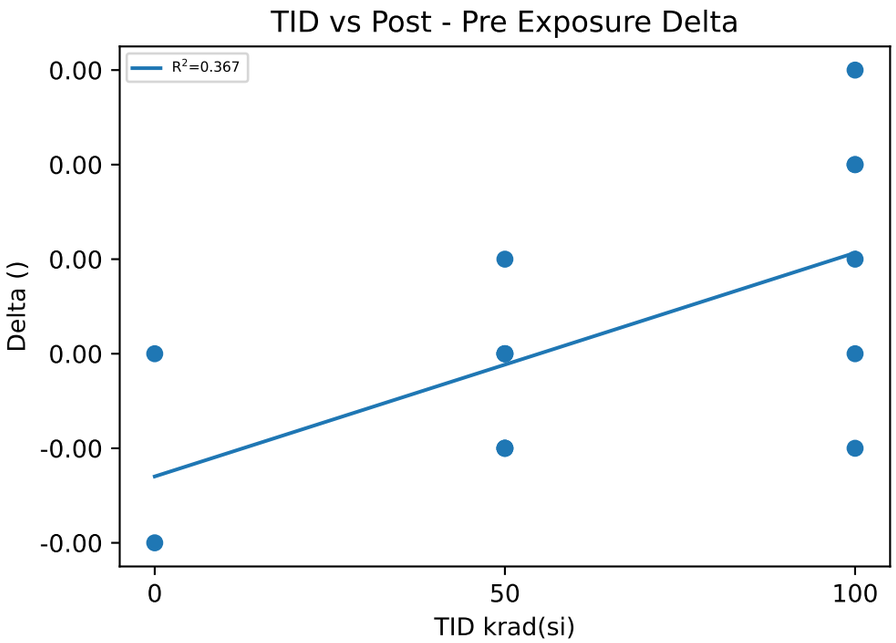
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.266	0.265	-0.001
89	50	Biased	0.264	0.266	0.002
90	50	Biased	0.258	0.259	0.001
92	50	Biased	0.266	0.267	0.001
93	50	Unbiased	0.26	0.259	-0.001
94	50	Unbiased	0.267	0.267	0
95	50	Unbiased	0.266	0.267	0.001
96	100	Biased	0.261	0.261	0
97	100	Biased	0.268	0.27	0.002
98	100	Biased	0.267	0.267	0
99	100	Unbiased	0.261	0.263	0.002
100	100	Unbiased	0.259	0.261	0.002
101	100	Unbiased	0.267	0.268	0.001
102	0	Correlation	0.269	0.268	-0.001
103	0	Correlation	0.267	0.266	-0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.267	0.268	0.269	0.0014142	0.266	0.267	0.268	0.0014142	-0.001	-0.001	-0.001	0
50	0.258	0.26386	0.267	0.0034847	0.259	0.26429	0.267	0.0036839	-0.001	0.00042857	0.002	0.0011339
100	0.259	0.26383	0.268	0.00392	0.261	0.265	0.27	0.0038471	0	0.0011667	0.002	0.00098319

Device Test: 5.24 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB2_SD/RESETB2/1.6/3/10.5K/0/0/@DLY_TMR_10KOHM)





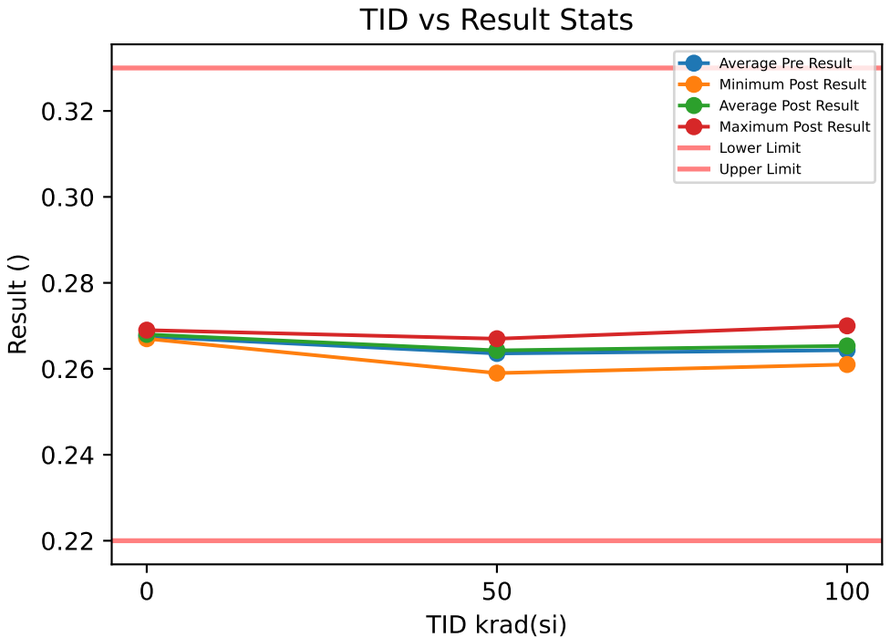
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

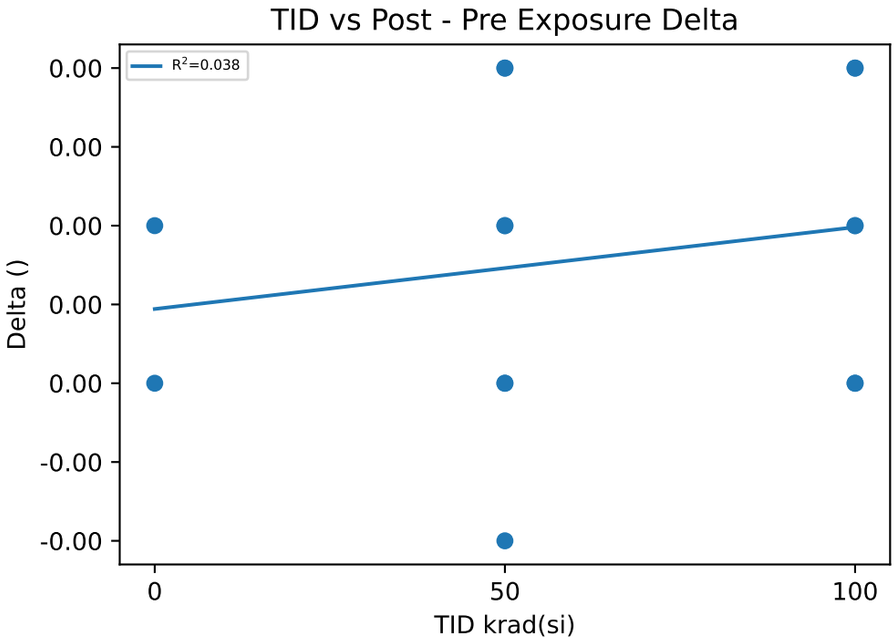
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.266	0.266	0
89	50	Biased	0.267	0.266	-0.001
90	50	Biased	0.259	0.258	-0.001
92	50	Biased	0.266	0.267	0.001
93	50	Unbiased	0.259	0.258	-0.001
94	50	Unbiased	0.268	0.268	0
95	50	Unbiased	0.266	0.266	0
96	100	Biased	0.262	0.261	-0.001
97	100	Biased	0.268	0.271	0.003
98	100	Biased	0.267	0.267	0
99	100	Unbiased	0.261	0.263	0.002
100	100	Unbiased	0.26	0.262	0.002
101	100	Unbiased	0.267	0.268	0.001
102	0	Correlation	0.269	0.267	-0.002
103	0	Correlation	0.267	0.267	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.267	0.268	0.269	0.0014142	0.267	0.267	0.267	0	-0.002	-0.001	0	0.0014142
50	0.259	0.26443	0.268	0.0037796	0.258	0.26414	0.268	0.0042594	-0.001	-0.00028571	0.001	0.00075593
100	0.26	0.26417	0.268	0.0035449	0.261	0.26533	0.271	0.0039328	-0.001	0.0011667	0.003	0.001472

Device Test: 5.25 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB4_SD/RESETB4/1.6/3/10.5K/0/0/@DLY_TMR_10KOHM)





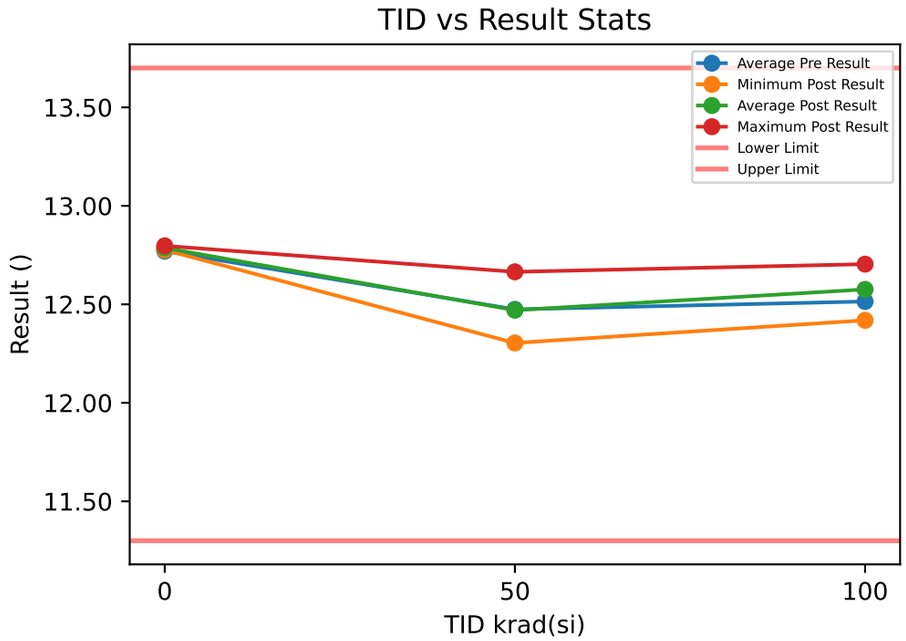
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

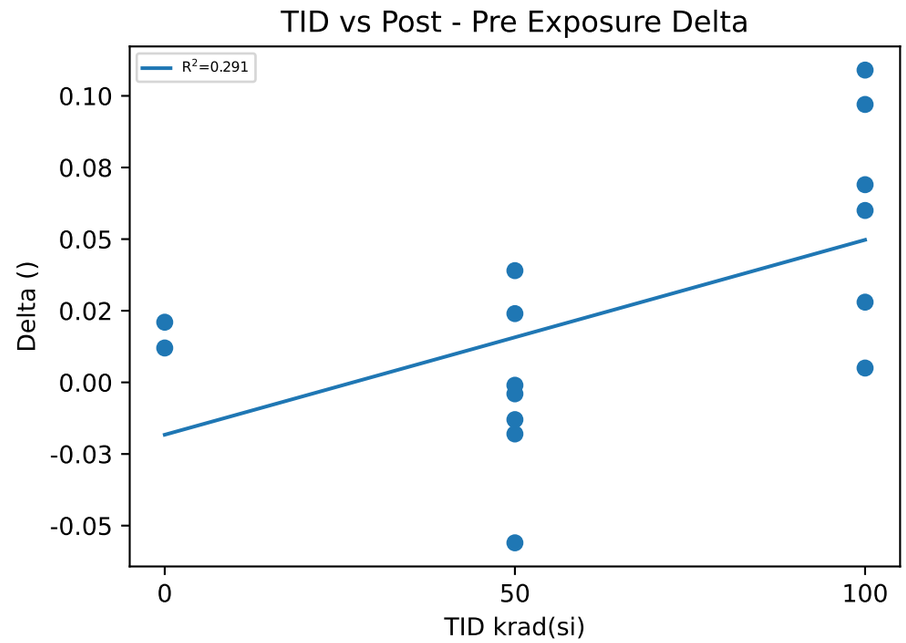
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.265	0.266	0.001
89	50	Biased	0.266	0.265	-0.001
90	50	Biased	0.257	0.259	0.002
92	50	Biased	0.267	0.267	0
93	50	Unbiased	0.258	0.26	0.002
94	50	Unbiased	0.267	0.267	0
95	50	Unbiased	0.265	0.266	0.001
96	100	Biased	0.26	0.262	0.002
97	100	Biased	0.268	0.27	0.002
98	100	Biased	0.268	0.269	0.001
99	100	Unbiased	0.261	0.262	0.001
100	100	Unbiased	0.261	0.261	0
101	100	Unbiased	0.268	0.268	0
102	0	Correlation	0.269	0.269	0
103	0	Correlation	0.266	0.267	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.266	0.2675	0.269	0.0021213	0.267	0.268	0.269	0.0014142	0	0.0005	0.001	0.00070711
50	0.257	0.26357	0.267	0.004237	0.259	0.26429	0.267	0.0033523	-0.001	0.00071429	0.002	0.0011127
100	0.26	0.26433	0.268	0.0040332	0.261	0.26533	0.27	0.0040825	0	0.001	0.002	0.00089443

Device Test: 5.26 DLY_TMR_500KOHM(tdly_Res619K_RESETB1_SU/RESETB1/1.6/3/619K/0/0/@DLY_TMR_500KOHM)





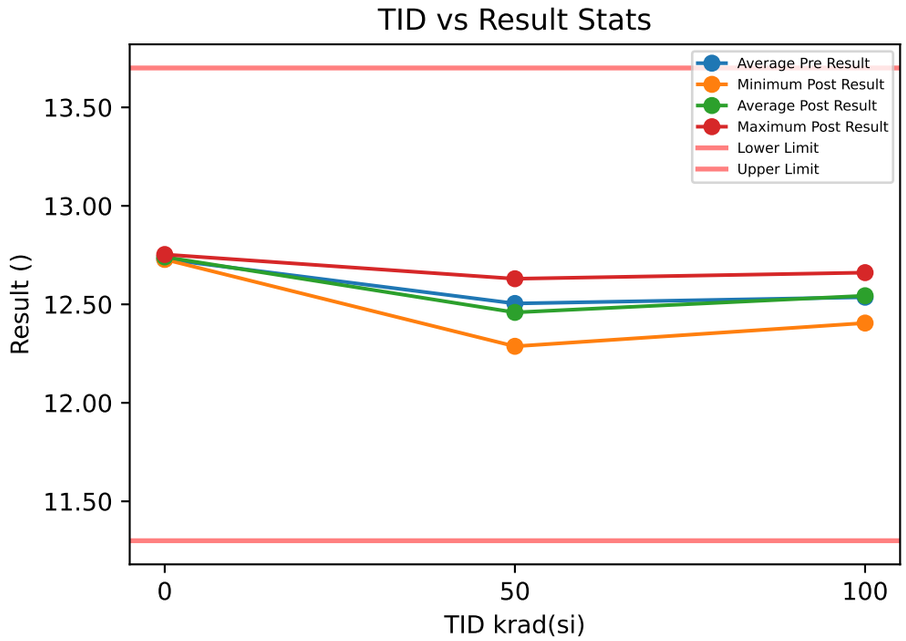
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

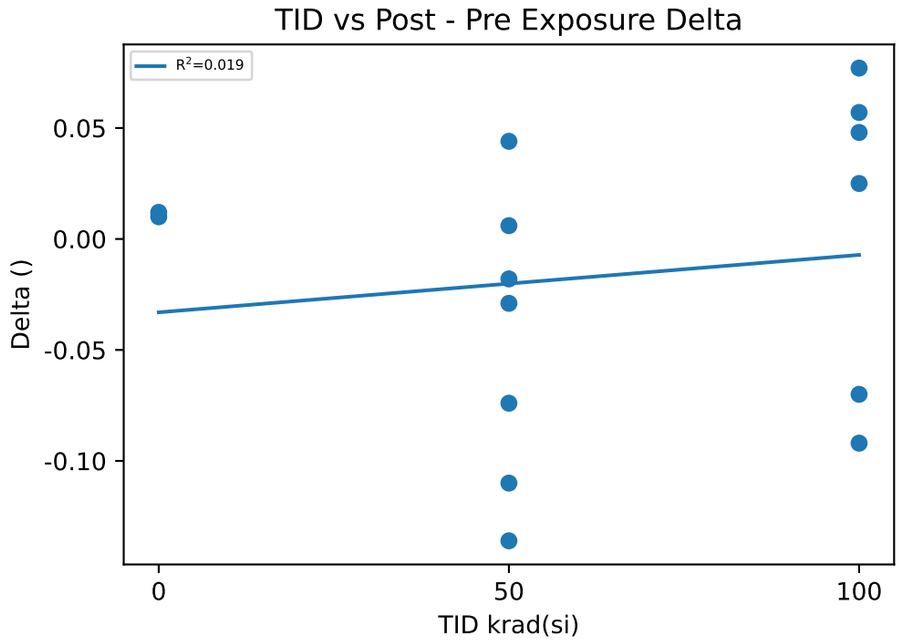
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.543	12.525	-0.018
89	50	Biased	12.626	12.665	0.039
90	50	Biased	12.392	12.391	-0.001
92	50	Biased	12.498	12.442	-0.056
93	50	Unbiased	12.28	12.304	0.024
94	50	Unbiased	12.525	12.521	-0.004
95	50	Unbiased	12.457	12.444	-0.013
96	100	Biased	12.416	12.444	0.028
97	100	Biased	12.561	12.67	0.109
98	100	Biased	12.503	12.572	0.069
99	100	Unbiased	12.644	12.704	0.06
100	100	Unbiased	12.414	12.419	0.005
101	100	Unbiased	12.549	12.646	0.097
102	0	Correlation	12.755	12.776	0.021
103	0	Correlation	12.785	12.797	0.012

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.755	12.77	12.785	0.021213	12.776	12.787	12.797	0.014849	0.012	0.0165	0.021	0.006364
50	12.28	12.474	12.626	0.11232	12.304	12.47	12.665	0.11468	-0.056	-0.0041429	0.039	0.030613
100	12.414	12.514	12.644	0.089507	12.419	12.576	12.704	0.12017	0.005	0.061333	0.109	0.039722

Device Test: 5.27 DLY_TMR_500KOHM(tdly_Res619K_RESETB3_SU/RESETB3/1.6/3/619K/0/0/@DLY_TMR_500KOHM)





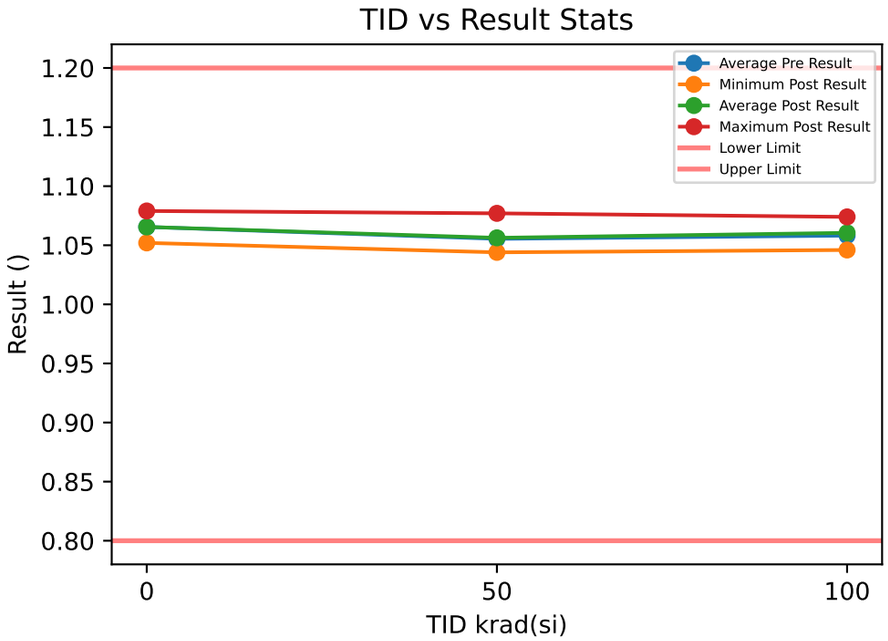
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

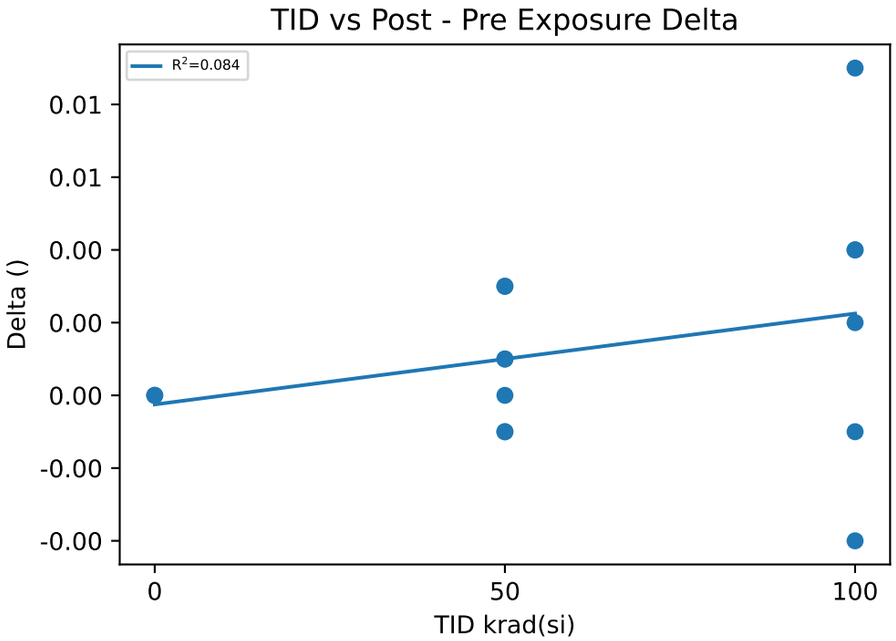
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.519	12.49	-0.029
89	50	Biased	12.586	12.63	0.044
90	50	Biased	12.478	12.368	-0.11
92	50	Biased	12.57	12.434	-0.136
93	50	Unbiased	12.361	12.287	-0.074
94	50	Unbiased	12.491	12.497	0.006
95	50	Unbiased	12.526	12.508	-0.018
96	100	Biased	12.499	12.429	-0.07
97	100	Biased	12.601	12.626	0.025
98	100	Biased	12.481	12.538	0.057
99	100	Unbiased	12.613	12.661	0.048
100	100	Unbiased	12.497	12.405	-0.092
101	100	Unbiased	12.526	12.603	0.077
102	0	Correlation	12.716	12.728	0.012
103	0	Correlation	12.743	12.753	0.01

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.716	12.729	12.743	0.019092	12.728	12.741	12.753	0.017678	0.01	0.011	0.012	0.0014142
50	12.361	12.504	12.586	0.074254	12.287	12.459	12.63	0.10995	-0.136	-0.045286	0.044	0.06436
100	12.481	12.536	12.613	0.056866	12.405	12.544	12.661	0.10628	-0.092	0.0075	0.077	0.070899

Device Test: 5.28 WD_TMR_500KOHM(twd_Res619K_WDOB_SU/WDOB/1.6/3/619K/0/0/@WD_TMR_500KOHM)





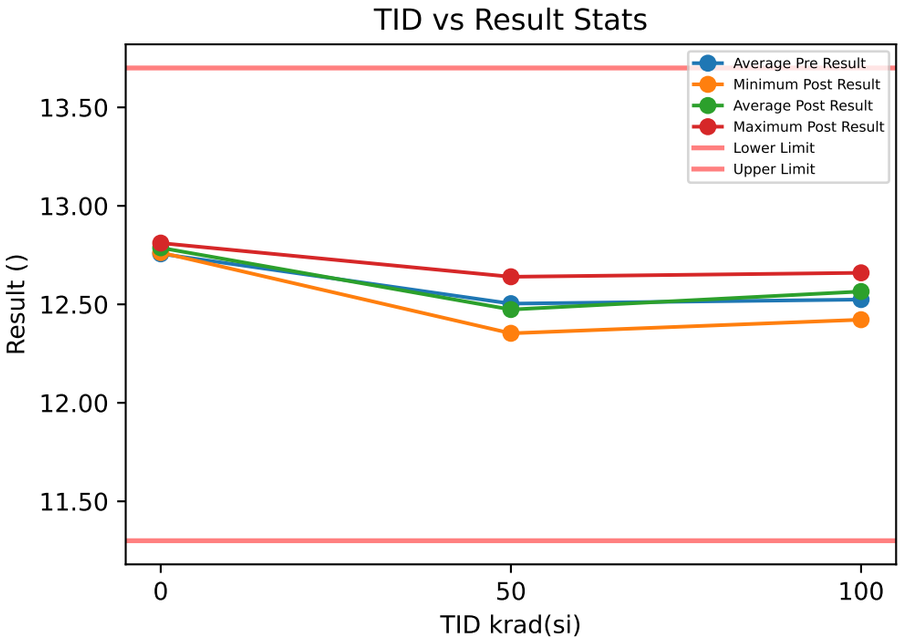
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 ())

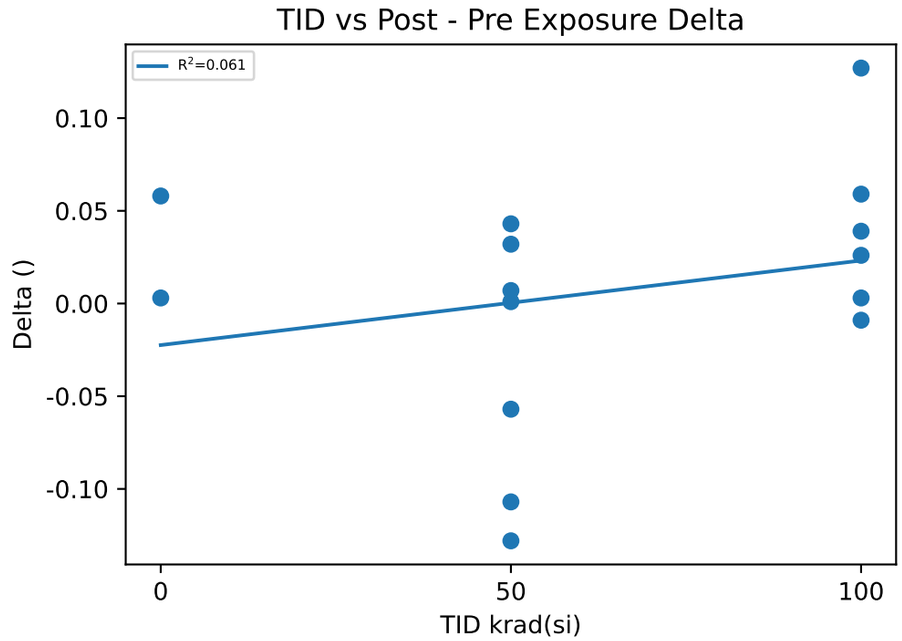
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.056	1.055	-0.001
89	50	Biased	1.041	1.044	0.003
90	50	Biased	1.044	1.045	0.001
92	50	Biased	1.065	1.066	0.001
93	50	Unbiased	1.043	1.046	0.003
94	50	Unbiased	1.078	1.077	-0.001
95	50	Unbiased	1.061	1.061	0
96	100	Biased	1.056	1.052	-0.004
97	100	Biased	1.064	1.066	0.002
98	100	Biased	1.047	1.046	-0.001
99	100	Unbiased	1.065	1.074	0.009
100	100	Unbiased	1.052	1.056	0.004
101	100	Unbiased	1.065	1.069	0.004
102	0	Correlation	1.079	1.079	0
103	0	Correlation	1.052	1.052	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.052	1.0655	1.079	0.019092	1.052	1.0655	1.079	0.019092	0	0	0	0
50	1.041	1.0554	1.078	0.013697	1.044	1.0563	1.077	0.012459	-0.001	0.00085714	0.003	0.0016762
100	1.047	1.0582	1.065	0.007679	1.046	1.0605	1.074	0.01084	-0.004	0.0023333	0.009	0.0045019

Device Test: 5.29 DLY_TMR_500KOHM(tdly_Res619K_PWRGD_SU/PWRGD/1.6/3/619K/0/0/@DLY_TMR_500KOHM)





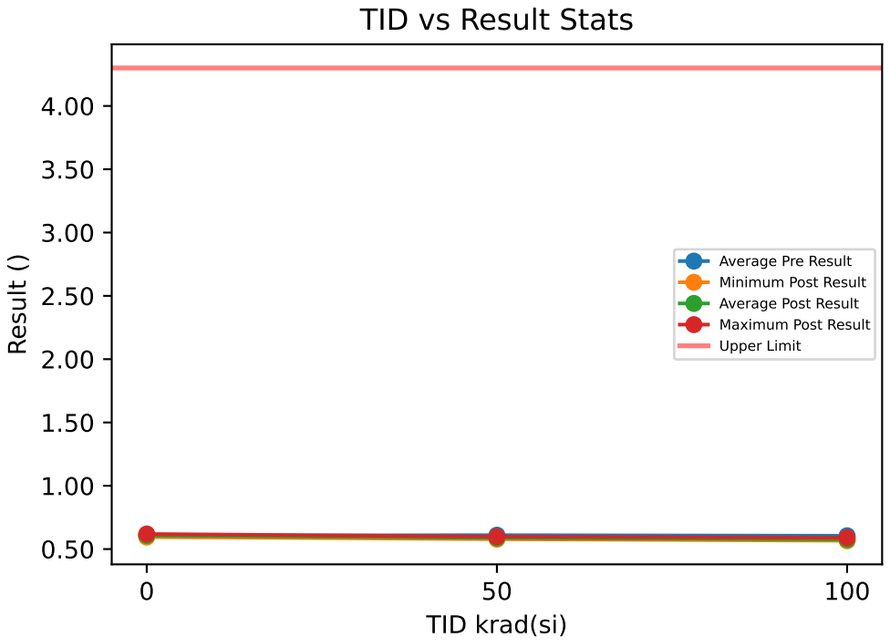
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

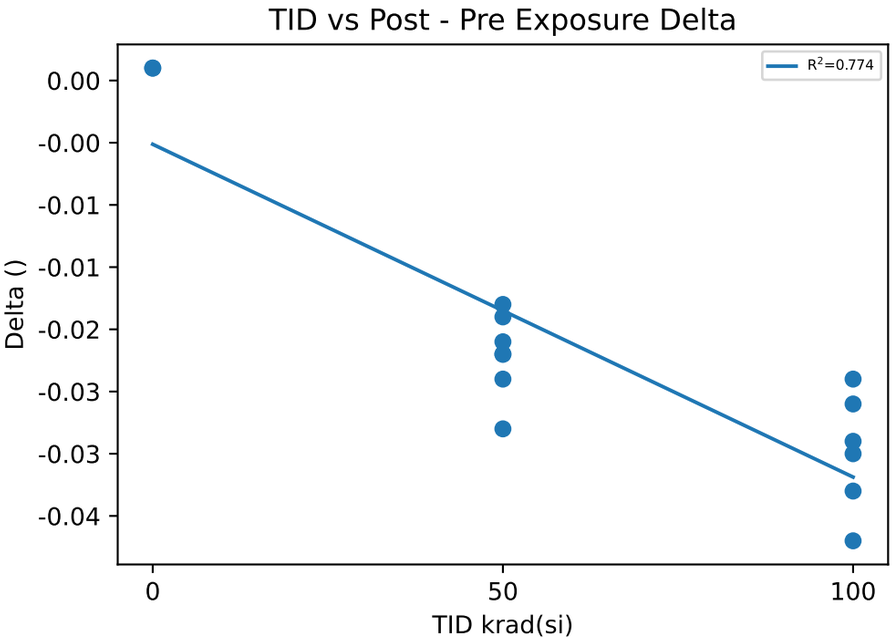
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.608	12.501	-0.107
89	50	Biased	12.639	12.64	0.001
90	50	Biased	12.4	12.407	0.007
92	50	Biased	12.563	12.435	-0.128
93	50	Unbiased	12.31	12.353	0.043
94	50	Unbiased	12.511	12.543	0.032
95	50	Unbiased	12.494	12.437	-0.057
96	100	Biased	12.419	12.422	0.003
97	100	Biased	12.533	12.66	0.127
98	100	Biased	12.565	12.556	-0.009
99	100	Unbiased	12.601	12.64	0.039
100	100	Unbiased	12.431	12.49	0.059
101	100	Unbiased	12.597	12.623	0.026
102	0	Correlation	12.705	12.763	0.058
103	0	Correlation	12.808	12.811	0.003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.705	12.756	12.808	0.072832	12.763	12.787	12.811	0.033941	0.003	0.0305	0.058	0.038891
50	12.31	12.504	12.639	0.11628	12.353	12.474	12.64	0.0958	-0.128	-0.029857	0.043	0.068026
100	12.419	12.524	12.601	0.080862	12.422	12.565	12.66	0.093988	-0.009	0.040833	0.127	0.048771

Device Test: 5.3 PROPD_RESET(tpd_RESETB2_SD/RESETB2/1.6/3/0/0/0/@PROPD_RESET)





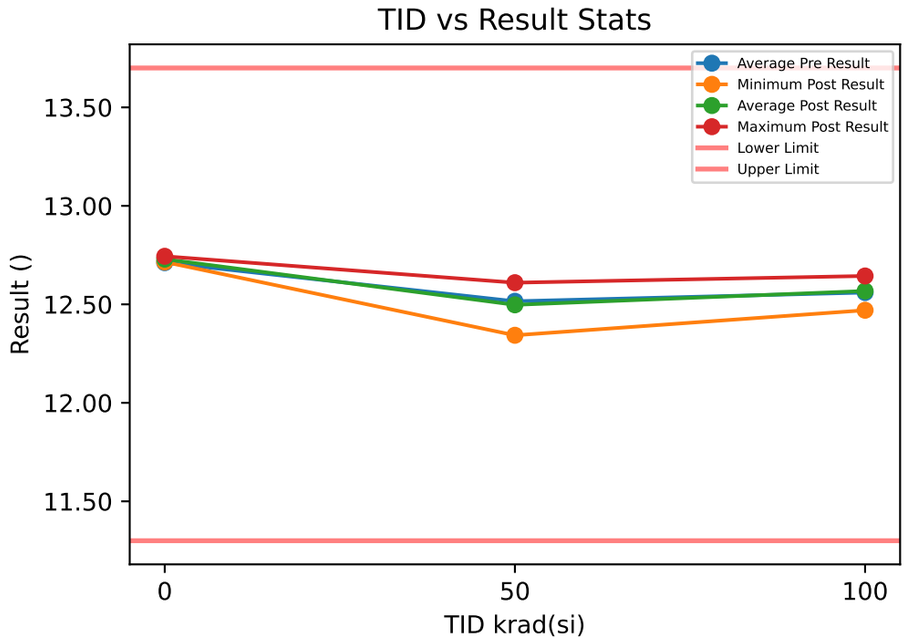
Test Results (Upper Limit = 4.3 ())

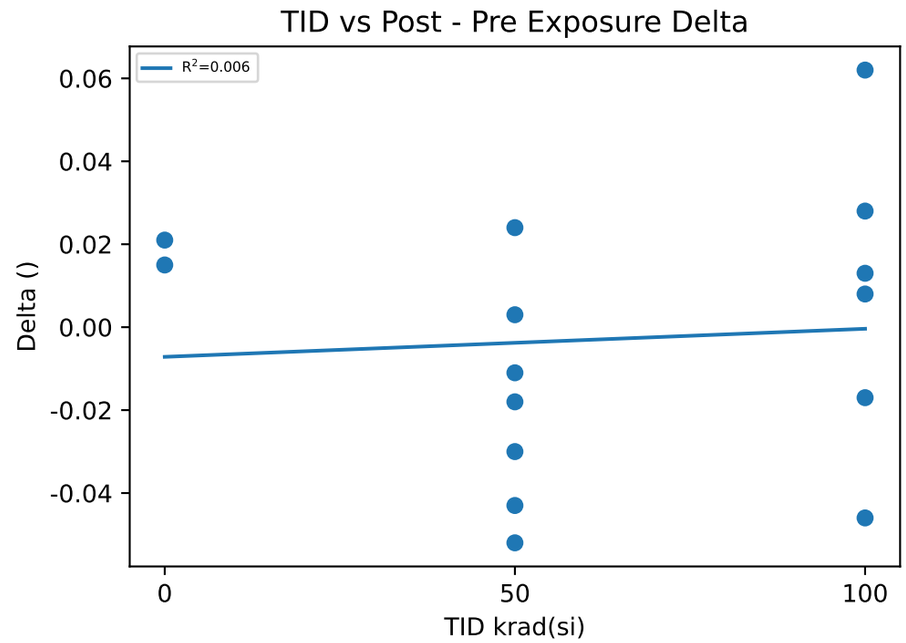
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.622	0.598	-0.024
89	50	Biased	0.603	0.585	-0.018
90	50	Biased	0.597	0.578	-0.019
92	50	Biased	0.605	0.583	-0.022
93	50	Unbiased	0.605	0.584	-0.021
94	50	Unbiased	0.618	0.59	-0.028
95	50	Unbiased	0.618	0.596	-0.022
96	100	Biased	0.6	0.567	-0.033
97	100	Biased	0.603	0.566	-0.037
98	100	Biased	0.597	0.573	-0.024
99	100	Unbiased	0.606	0.576	-0.03
100	100	Unbiased	0.616	0.59	-0.026
101	100	Unbiased	0.609	0.58	-0.029
102	0	Correlation	0.594	0.595	0.001
103	0	Correlation	0.618	0.619	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.594	0.606	0.618	0.016971	0.595	0.607	0.619	0.016971	0.001	0.001	0.001	0
50	0.597	0.60971	0.622	0.0094818	0.578	0.58771	0.598	0.0072736	-0.028	-0.022	-0.018	0.0033166
100	0.597	0.60517	0.616	0.0067946	0.566	0.57533	0.59	0.0089368	-0.037	-0.029833	-0.024	0.0047081

Device Test: 5.30 DLY_TMR_500KOHM(tdly_Res619K_RESETB2_SD/RESETB2/1.6/3/619K/0/0/@DLY_TMR_500KOHM)





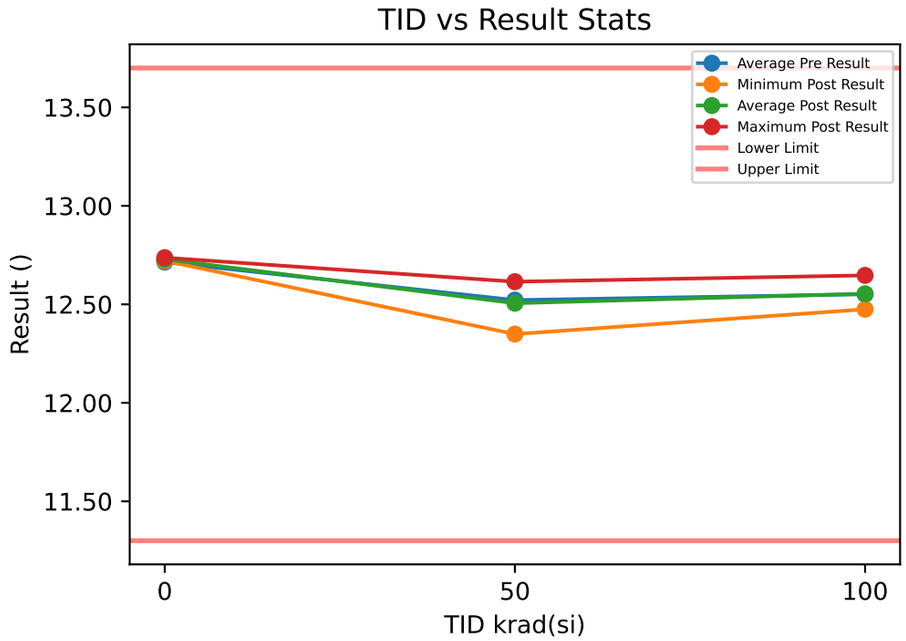
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

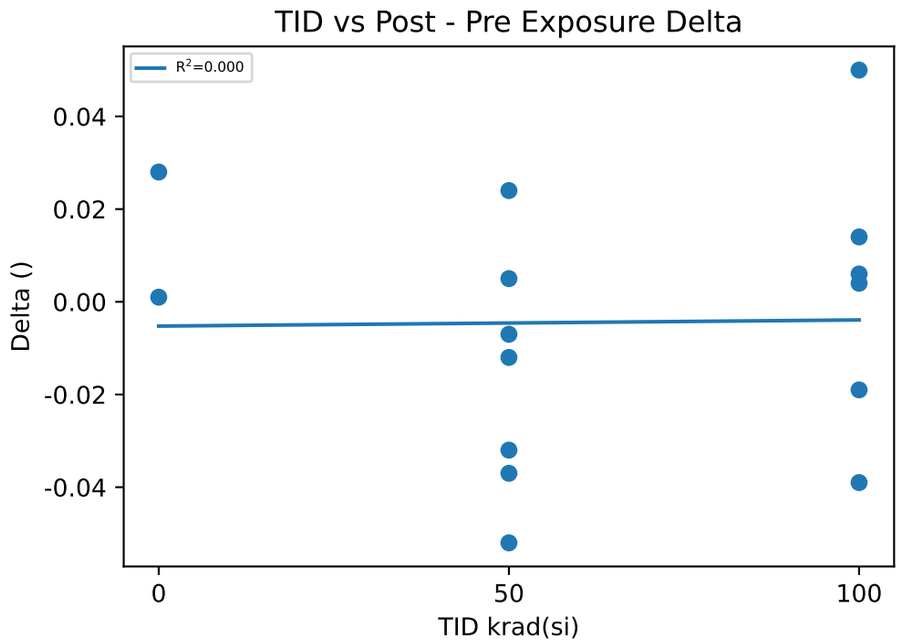
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.591	12.561	-0.03
89	50	Biased	12.662	12.61	-0.052
90	50	Biased	12.441	12.43	-0.011
92	50	Biased	12.544	12.501	-0.043
93	50	Unbiased	12.319	12.343	0.024
94	50	Unbiased	12.56	12.563	0.003
95	50	Unbiased	12.493	12.475	-0.018
96	100	Biased	12.467	12.495	0.028
97	100	Biased	12.593	12.606	0.013
98	100	Biased	12.549	12.611	0.062
99	100	Unbiased	12.69	12.644	-0.046
100	100	Unbiased	12.462	12.47	0.008
101	100	Unbiased	12.598	12.581	-0.017
102	0	Correlation	12.694	12.715	0.021
103	0	Correlation	12.729	12.744	0.015

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.694	12.712	12.729	0.024749	12.715	12.729	12.744	0.020506	0.015	0.018	0.021	0.0042426
50	12.319	12.516	12.662	0.11152	12.343	12.498	12.61	0.091217	-0.052	-0.018143	0.024	0.026391
100	12.462	12.56	12.69	0.086956	12.47	12.568	12.644	0.069528	-0.046	0.008	0.062	0.0371

Device Test: 5.31 DLY_TMR_500KOHM(tdly_Res619K_RESETB4_SD/RESETB4/1.6/3/619K/0/0/@DLY_TMR_500KOHM)





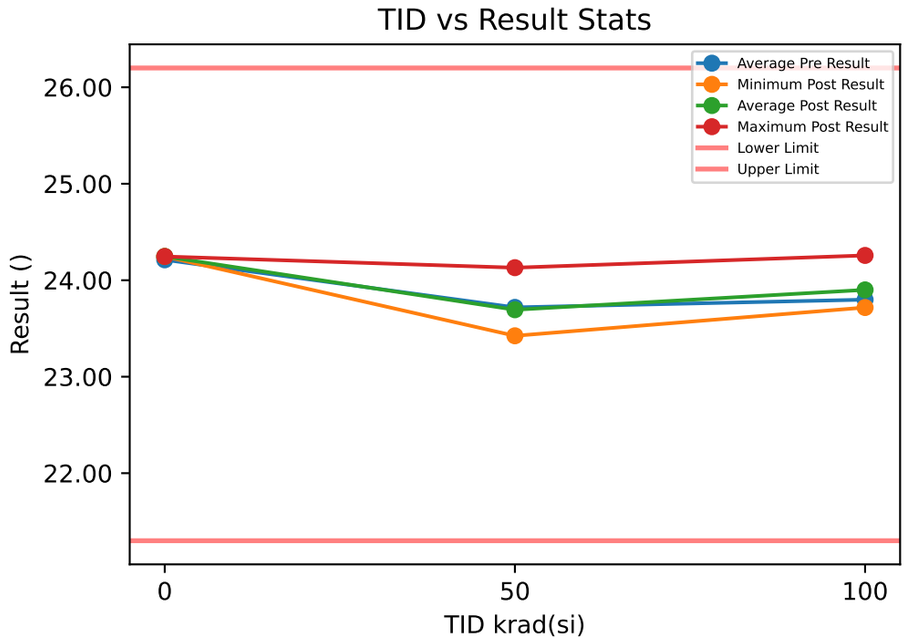
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

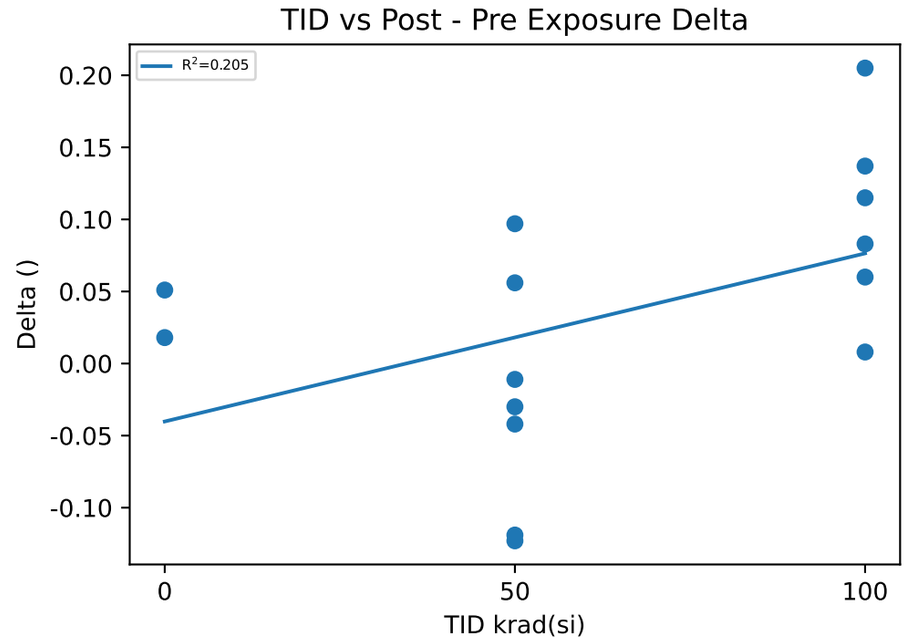
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.598	12.566	-0.032
89	50	Biased	12.652	12.615	-0.037
90	50	Biased	12.448	12.436	-0.012
92	50	Biased	12.56	12.508	-0.052
93	50	Unbiased	12.325	12.349	0.024
94	50	Unbiased	12.567	12.572	0.005
95	50	Unbiased	12.501	12.494	-0.007
96	100	Biased	12.473	12.487	0.014
97	100	Biased	12.606	12.61	0.004
98	100	Biased	12.557	12.518	-0.039
99	100	Unbiased	12.597	12.647	0.05
100	100	Unbiased	12.469	12.475	0.006
101	100	Unbiased	12.605	12.586	-0.019
102	0	Correlation	12.693	12.721	0.028
103	0	Correlation	12.736	12.737	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.693	12.715	12.736	0.030406	12.721	12.729	12.737	0.011314	0.001	0.0145	0.028	0.019092
50	12.325	12.522	12.652	0.10868	12.349	12.506	12.615	0.09086	-0.052	-0.015857	0.024	0.026239
100	12.469	12.551	12.606	0.064654	12.475	12.554	12.647	0.070477	-0.039	0.0026667	0.05	0.03029

Device Test: 5.32 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB1_SU/RESETB1/1.6/3/1.18M/0/0/@DLY_TMR_1MOHM)





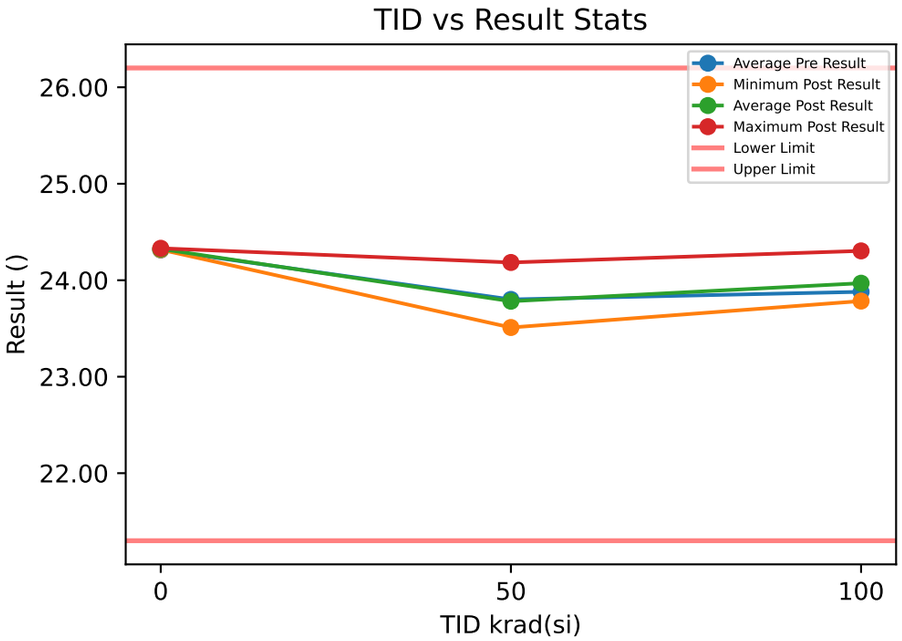
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

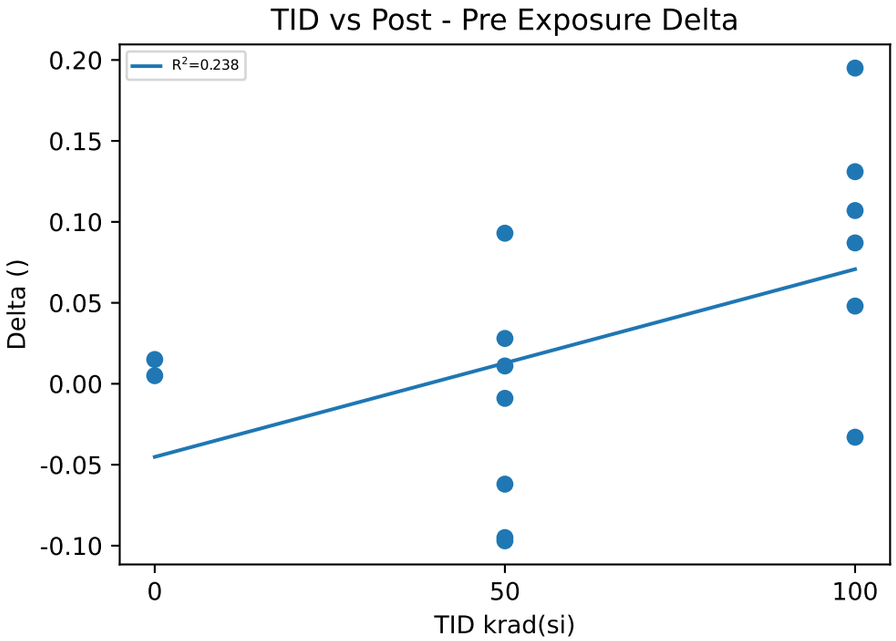
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.793	23.674	-0.119
89	50	Biased	24.033	24.13	0.097
90	50	Biased	23.745	23.703	-0.042
92	50	Biased	23.756	23.633	-0.123
93	50	Unbiased	23.368	23.424	0.056
94	50	Unbiased	23.726	23.696	-0.03
95	50	Unbiased	23.609	23.598	-0.011
96	100	Biased	23.712	23.772	0.06
97	100	Biased	23.779	23.984	0.205
98	100	Biased	23.634	23.717	0.083
99	100	Unbiased	24.142	24.257	0.115
100	100	Unbiased	23.725	23.733	0.008
101	100	Unbiased	23.8	23.937	0.137
102	0	Correlation	24.195	24.246	0.051
103	0	Correlation	24.228	24.246	0.018

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.195	24.212	24.228	0.023335	24.246	24.246	24.246	0	0.018	0.0345	0.051	0.023335
50	23.368	23.719	24.033	0.20061	23.424	23.694	24.13	0.21464	-0.123	-0.024571	0.097	0.082051
100	23.634	23.799	24.142	0.17794	23.717	23.9	24.257	0.20671	0.008	0.10133	0.205	0.067766

Device Test: 5.33 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB3_SU/RESETB3/1.6/3/1.18M/0/0/@DLY_TMR_1MOHM)





Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

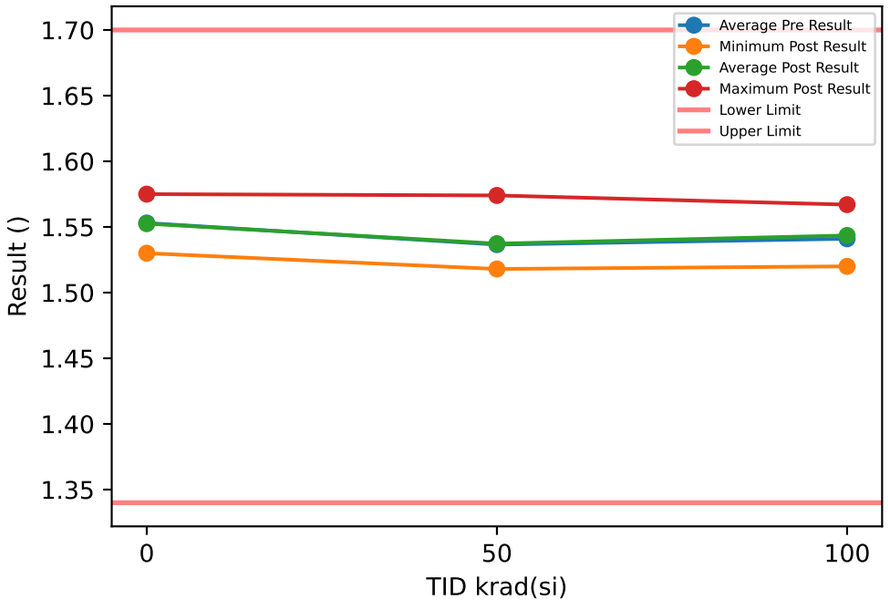
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.865	23.768	-0.097
89	50	Biased	24.091	24.184	0.093
90	50	Biased	23.836	23.774	-0.062
92	50	Biased	23.824	23.729	-0.095
93	50	Unbiased	23.482	23.51	0.028
94	50	Unbiased	23.8	23.791	-0.009
95	50	Unbiased	23.709	23.72	0.011
96	100	Biased	23.805	23.853	0.048
97	100	Biased	23.848	24.043	0.195
98	100	Biased	23.744	23.831	0.087
99	100	Unbiased	24.197	24.304	0.107
100	100	Unbiased	23.817	23.784	-0.033
101	100	Unbiased	23.868	23.999	0.131
102	0	Correlation	24.302	24.317	0.015
103	0	Correlation	24.326	24.331	0.005

Test Statistics ()

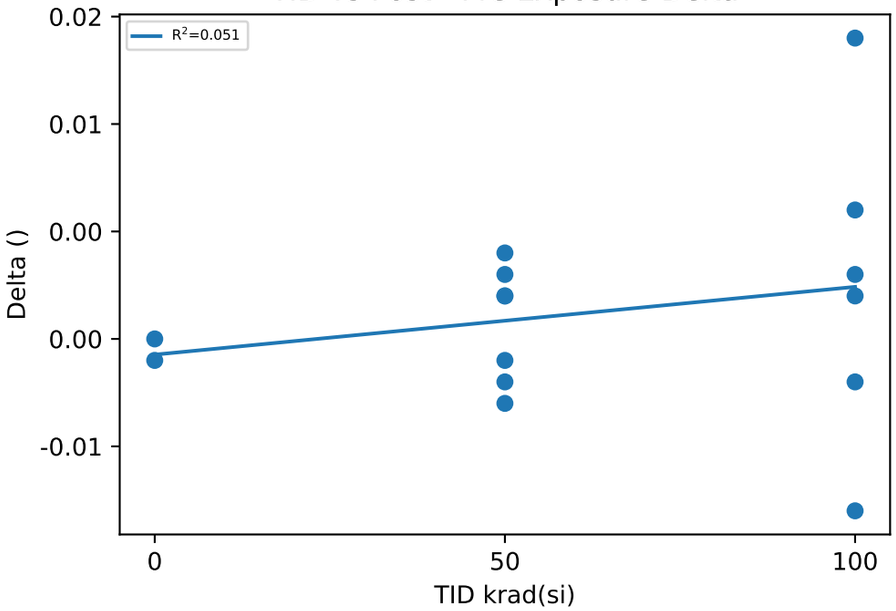
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.302	24.314	24.326	0.016971	24.317	24.324	24.331	0.0098995	0.005	0.01	0.015	0.0070711
50	23.482	23.801	24.091	0.18265	23.51	23.782	24.184	0.20107	-0.097	-0.018714	0.093	0.070073
100	23.744	23.88	24.197	0.16109	23.784	23.969	24.304	0.19252	-0.033	0.089167	0.195	0.077321

Device Test: 5.34 WD_TMR_1MOHM(twd_Res1p18M_WDOB_SU/WDOB/1.6/3/1.18M/0/0/@WD_TMR_1MOHM)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



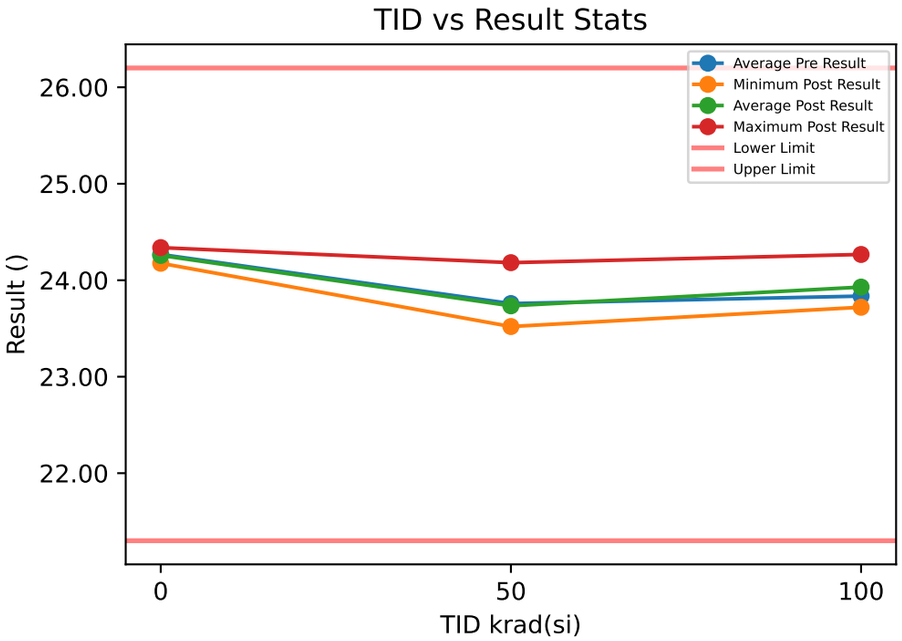
Test Results (Lower Limit = 1.34, Upper Limit = 1.7 ())

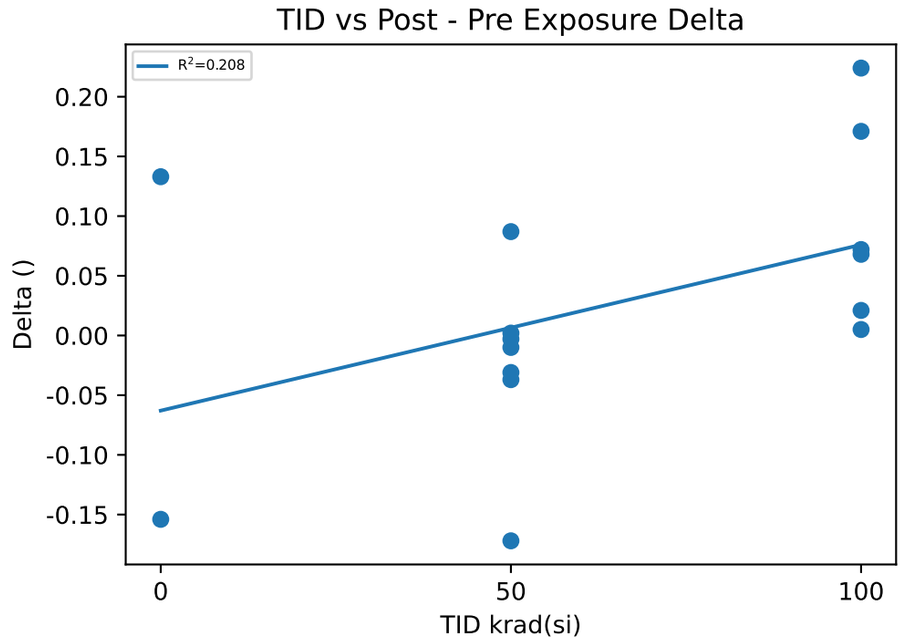
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.537	1.534	-0.003
89	50	Biased	1.514	1.518	0.004
90	50	Biased	1.516	1.518	0.002
92	50	Biased	1.552	1.554	0.002
93	50	Unbiased	1.516	1.519	0.003
94	50	Unbiased	1.575	1.574	-0.001
95	50	Unbiased	1.546	1.544	-0.002
96	100	Biased	1.538	1.53	-0.008
97	100	Biased	1.55	1.552	0.002
98	100	Biased	1.522	1.52	-0.002
99	100	Unbiased	1.553	1.567	0.014
100	100	Unbiased	1.531	1.534	0.003
101	100	Unbiased	1.552	1.558	0.006
102	0	Correlation	1.576	1.575	-0.001
103	0	Correlation	1.53	1.53	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.53	1.553	1.576	0.032527	1.53	1.5525	1.575	0.03182	-0.001	-0.0005	0	0.00070711
50	1.514	1.5366	1.575	0.022948	1.518	1.5373	1.574	0.021453	-0.003	0.00071429	0.004	0.0026904
100	1.522	1.541	1.553	0.012775	1.52	1.5435	1.567	0.018218	-0.008	0.0025	0.014	0.0074229

Device Test: 5.35 DLY_TMR_1MOHM(tdly_Res1p18M_PWRGD_SU/PWRGD/1.6/3/1.18M/0/0/@DLY_TMR_1MOHM)





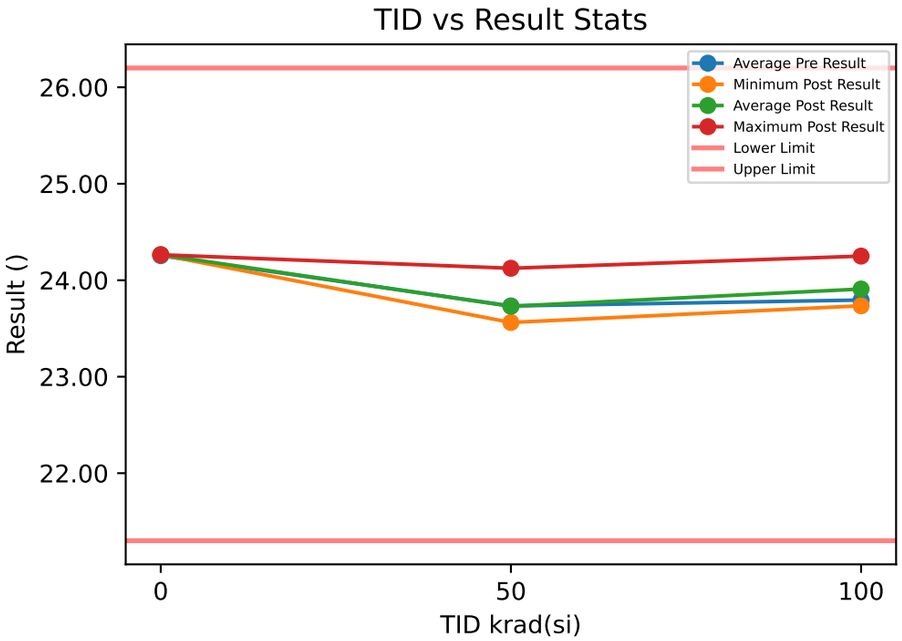
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

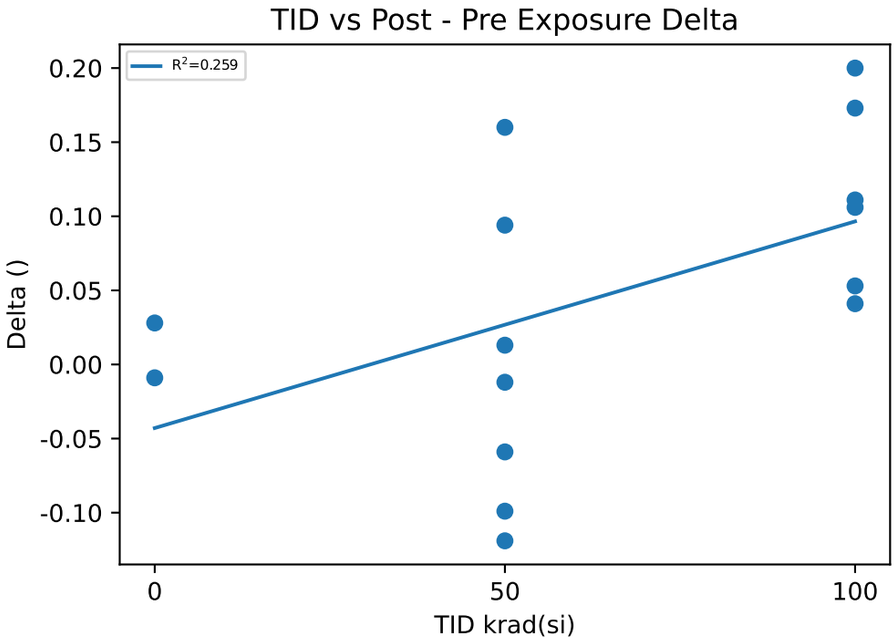
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.8	23.763	-0.037
89	50	Biased	24.095	24.182	0.087
90	50	Biased	23.731	23.728	-0.003
92	50	Biased	23.797	23.625	-0.172
93	50	Unbiased	23.551	23.52	-0.031
94	50	Unbiased	23.718	23.72	0.002
95	50	Unbiased	23.615	23.605	-0.01
96	100	Biased	23.681	23.905	0.224
97	100	Biased	23.878	23.899	0.021
98	100	Biased	23.688	23.859	0.171
99	100	Unbiased	24.195	24.267	0.072
100	100	Unbiased	23.715	23.72	0.005
101	100	Unbiased	23.856	23.924	0.068
102	0	Correlation	24.33	24.176	-0.154
103	0	Correlation	24.205	24.338	0.133

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.205	24.267	24.33	0.088388	24.176	24.257	24.338	0.11455	-0.154	-0.0105	0.133	0.20294
50	23.551	23.758	24.095	0.17439	23.52	23.735	24.182	0.21451	-0.172	-0.023429	0.087	0.077194
100	23.681	23.835	24.195	0.19576	23.72	23.929	24.267	0.18129	0.005	0.0935	0.224	0.086299

Device Test: 5.36 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB2_SD/RESETB2/1.6/3/1.18M/0/0/@DLY_TMR_1MOHM)





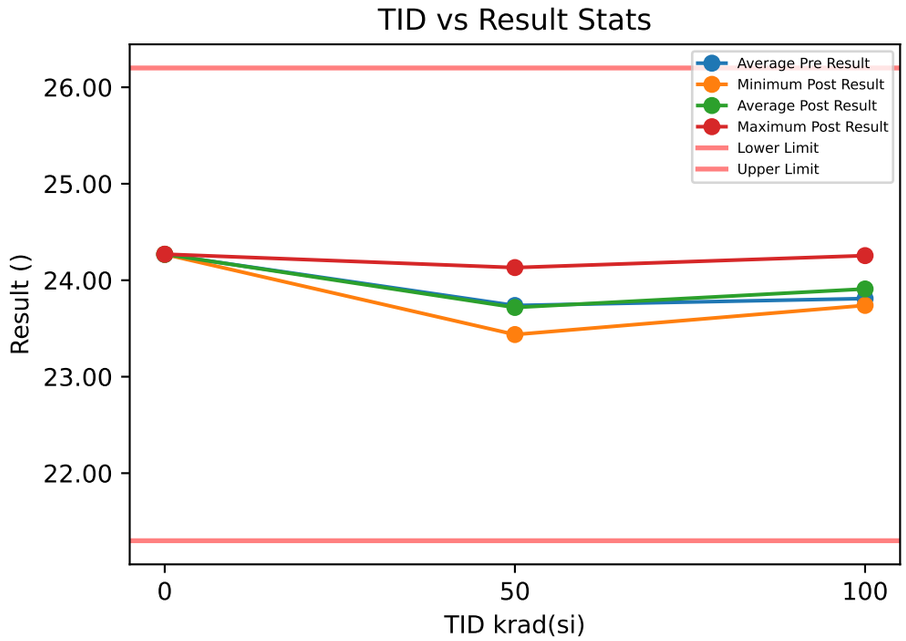
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

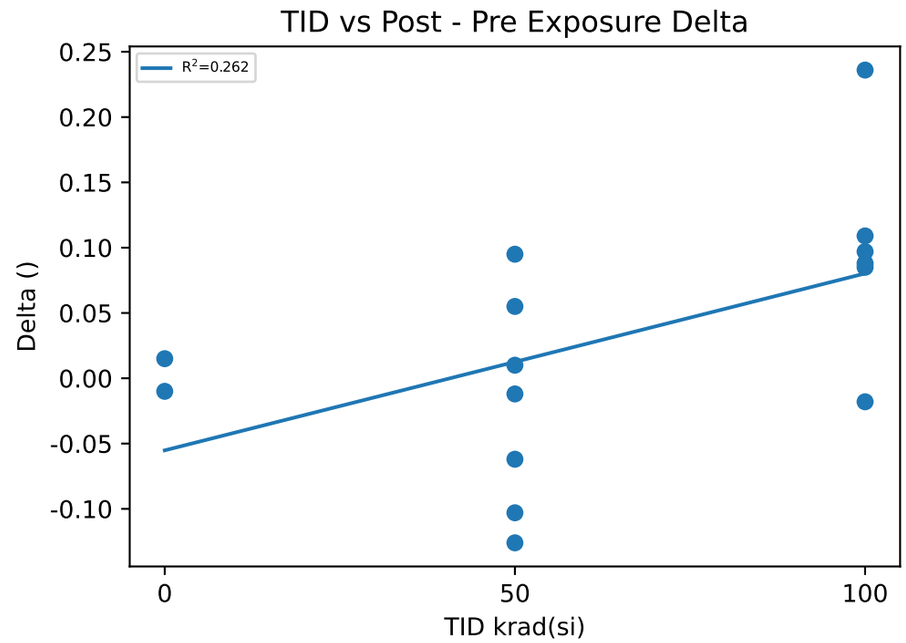
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.797	23.698	-0.099
89	50	Biased	24.03	24.124	0.094
90	50	Biased	23.764	23.705	-0.059
92	50	Biased	23.777	23.658	-0.119
93	50	Unbiased	23.402	23.562	0.16
94	50	Unbiased	23.727	23.715	-0.012
95	50	Unbiased	23.636	23.649	0.013
96	100	Biased	23.736	23.789	0.053
97	100	Biased	23.781	23.981	0.2
98	100	Biased	23.655	23.761	0.106
99	100	Unbiased	24.139	24.25	0.111
100	100	Unbiased	23.694	23.735	0.041
101	100	Unbiased	23.764	23.937	0.173
102	0	Correlation	24.236	24.264	0.028
103	0	Correlation	24.273	24.264	-0.009

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.236	24.255	24.273	0.026163	24.264	24.264	24.264	0	-0.009	0.0095	0.028	0.026163
50	23.402	23.733	24.03	0.18895	23.562	23.73	24.124	0.18124	-0.119	-0.0031429	0.16	0.10175
100	23.655	23.795	24.139	0.1748	23.735	23.909	24.25	0.19433	0.041	0.114	0.2	0.063246

Device Test: 5.37 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB4_SD/RESETB4/1.6/3/1.18M/0/0/@DLY_TMR_1MOHM)





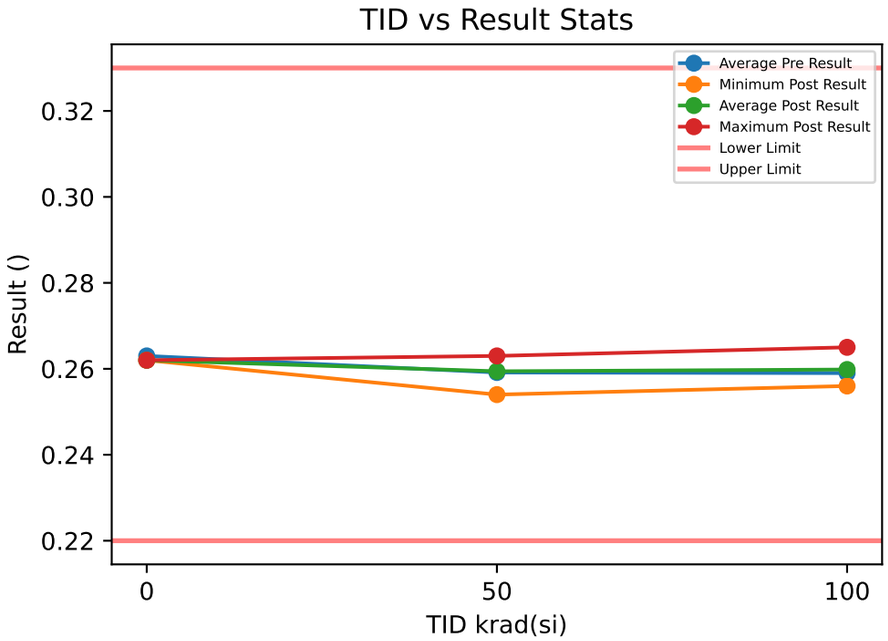
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

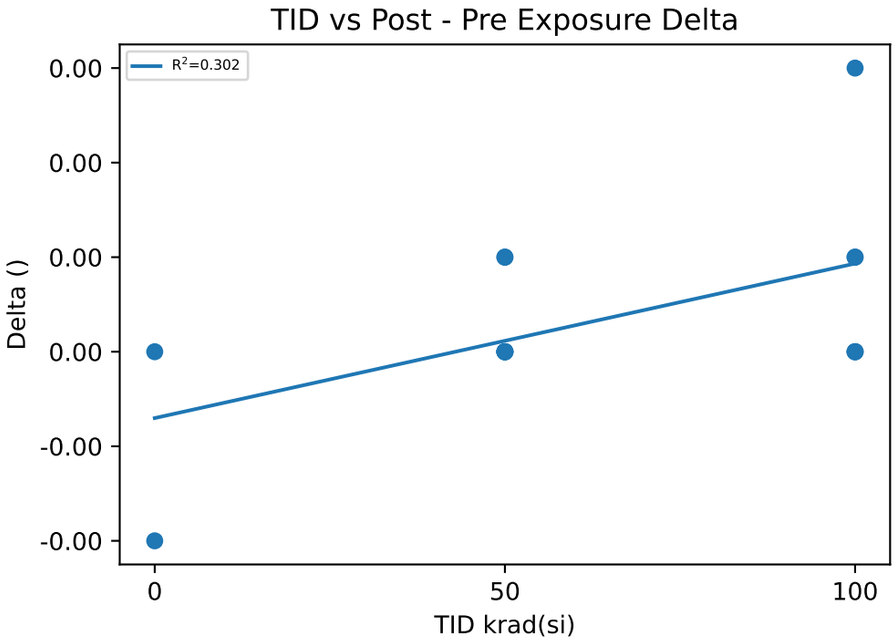
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.804	23.701	-0.103
89	50	Biased	24.036	24.131	0.095
90	50	Biased	23.773	23.711	-0.062
92	50	Biased	23.79	23.664	-0.126
93	50	Unbiased	23.382	23.437	0.055
94	50	Unbiased	23.739	23.727	-0.012
95	50	Unbiased	23.643	23.653	0.01
96	100	Biased	23.717	23.802	0.085
97	100	Biased	23.751	23.987	0.236
98	100	Biased	23.679	23.767	0.088
99	100	Unbiased	24.146	24.255	0.109
100	100	Unbiased	23.757	23.739	-0.018
101	100	Unbiased	23.81	23.907	0.097
102	0	Correlation	24.255	24.27	0.015
103	0	Correlation	24.278	24.268	-0.01

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.255	24.267	24.278	0.016263	24.268	24.269	24.27	0.0014142	-0.01	0.0025	0.015	0.017678
50	23.382	23.738	24.036	0.197	23.437	23.718	24.131	0.207	-0.126	-0.020429	0.095	0.081345
100	23.679	23.81	24.146	0.17029	23.739	23.909	24.255	0.19304	-0.018	0.0995	0.236	0.081089

Device Test: 5.38 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB1_SU/RESETB1/1.6/14/10.5K/0/0/@DLY_TMR_10KOHM





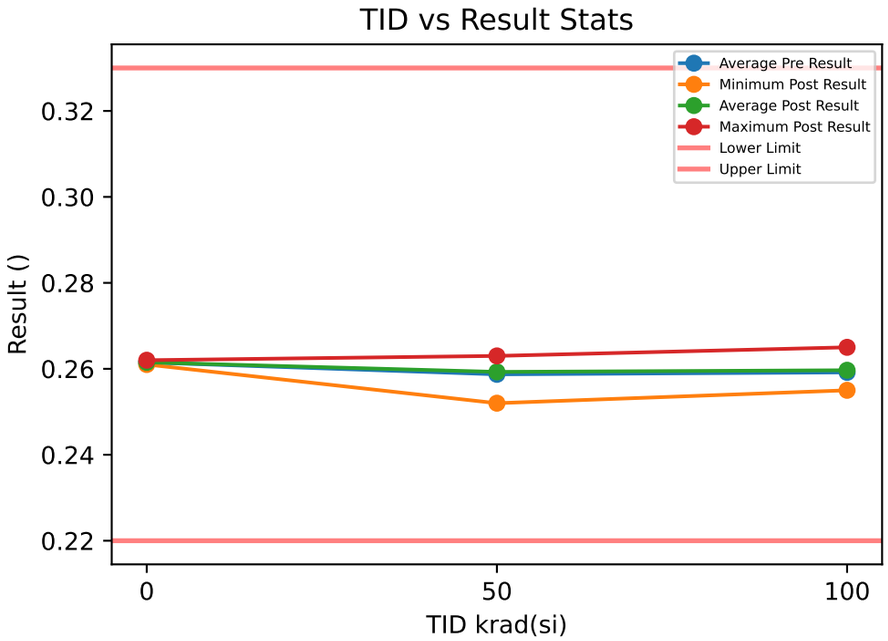
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

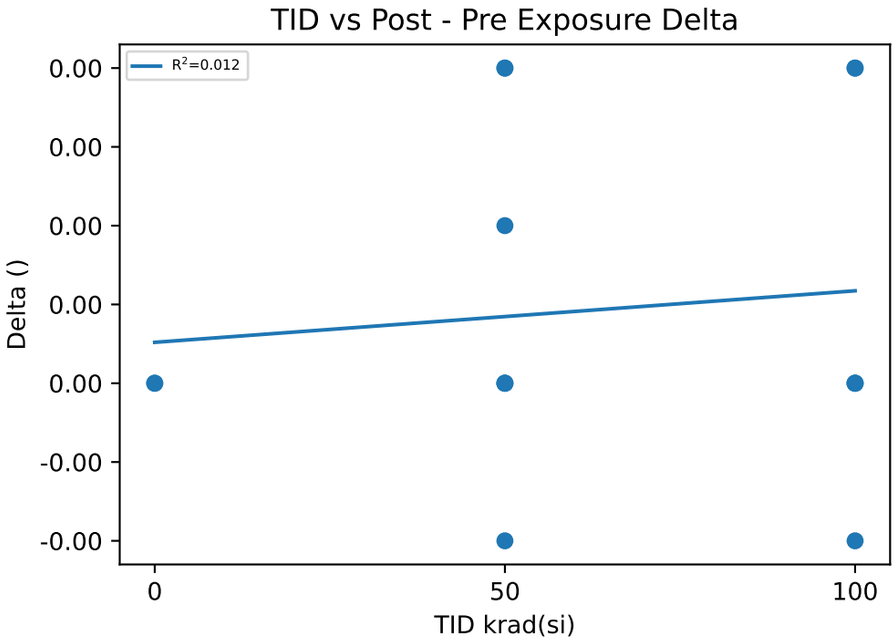
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.261	0.262	0.001
89	50	Biased	0.26	0.26	0
90	50	Biased	0.254	0.254	0
92	50	Biased	0.261	0.261	0
93	50	Unbiased	0.254	0.255	0.001
94	50	Unbiased	0.263	0.263	0
95	50	Unbiased	0.261	0.261	0
96	100	Biased	0.256	0.256	0
97	100	Biased	0.264	0.265	0.001
98	100	Biased	0.261	0.262	0.001
99	100	Unbiased	0.256	0.256	0
100	100	Unbiased	0.256	0.256	0
101	100	Unbiased	0.261	0.264	0.003
102	0	Correlation	0.264	0.262	-0.002
103	0	Correlation	0.262	0.262	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.262	0.263	0.264	0.0014142	0.262	0.262	0.262	0	-0.002	-0.001	0	0.0014142
50	0.254	0.25914	0.263	0.0036253	0.254	0.25943	0.263	0.0035051	0	0.00028571	0.001	0.00048795
100	0.256	0.259	0.264	0.0034641	0.256	0.25983	0.265	0.0043089	0	0.00083333	0.003	0.001169

Device Test: 5.39 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB3_SU/RESETB3/1.6/14/10.5K/0/0/@DLY_TMR_10KOHM





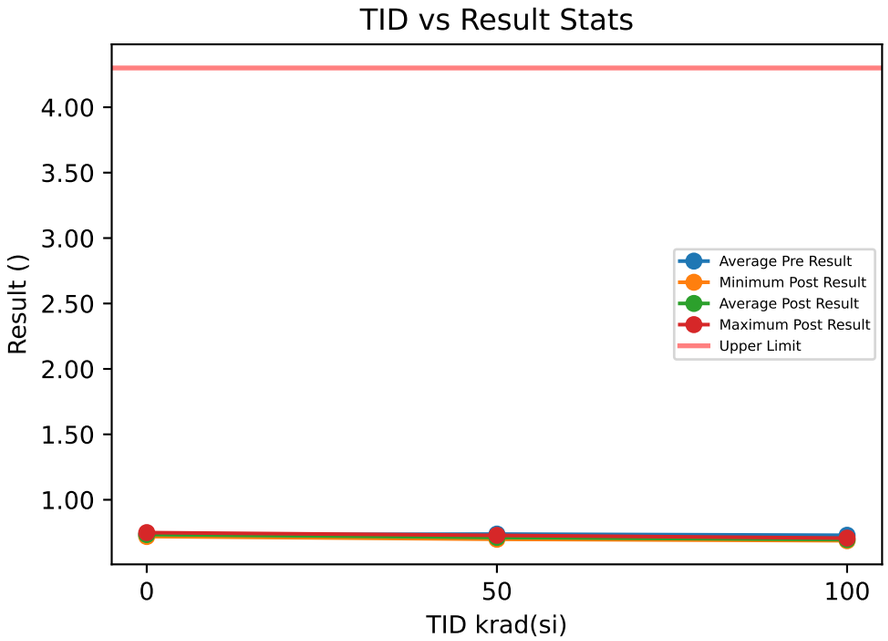
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

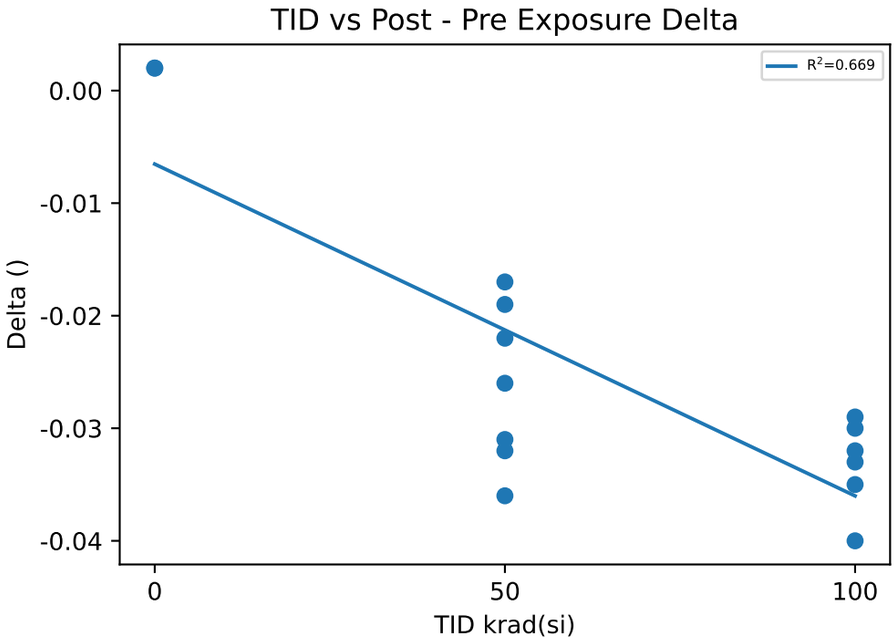
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.26	0.262	0.002
89	50	Biased	0.26	0.26	0
90	50	Biased	0.253	0.252	-0.001
92	50	Biased	0.261	0.261	0
93	50	Unbiased	0.253	0.255	0.002
94	50	Unbiased	0.262	0.263	0.001
95	50	Unbiased	0.262	0.262	0
96	100	Biased	0.256	0.256	0
97	100	Biased	0.263	0.265	0.002
98	100	Biased	0.262	0.261	-0.001
99	100	Unbiased	0.257	0.257	0
100	100	Unbiased	0.255	0.255	0
101	100	Unbiased	0.262	0.264	0.002
102	0	Correlation	0.262	0.262	0
103	0	Correlation	0.261	0.261	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.261	0.2615	0.262	0.00070711	0.261	0.2615	0.262	0.00070711	0	0	0	0
50	0.253	0.25871	0.262	0.0039881	0.252	0.25929	0.263	0.0041519	-0.001	0.00057143	0.002	0.0011339
100	0.255	0.25917	0.263	0.0035449	0.255	0.25967	0.265	0.004274	-0.001	0.0005	0.002	0.0012247

Device Test: 5.4 PROPD_RESET(tpd_RESETB4_SD/RESETB4/1.6/3/0/0/0/@PROPD_RESET)





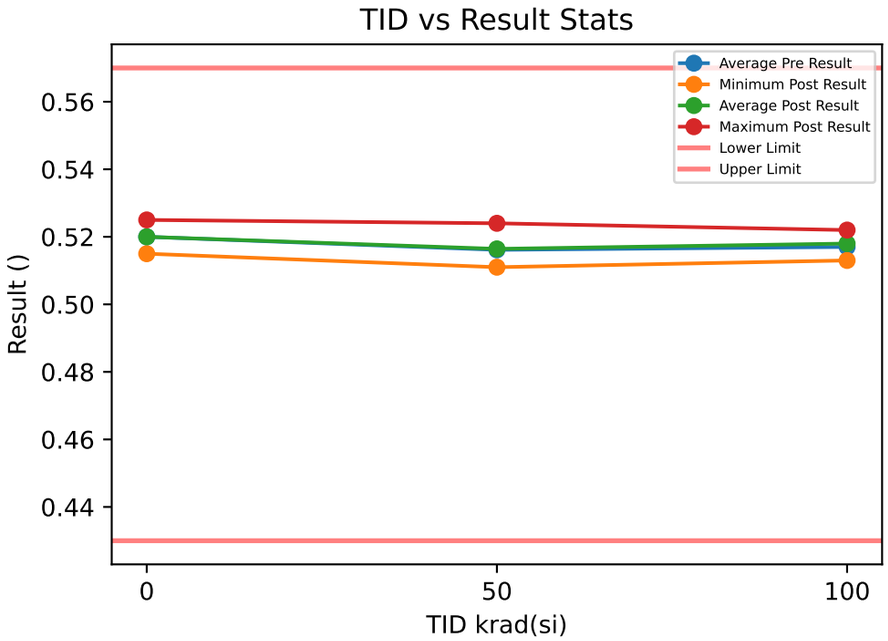
Test Results (Upper Limit = 4.3 ())

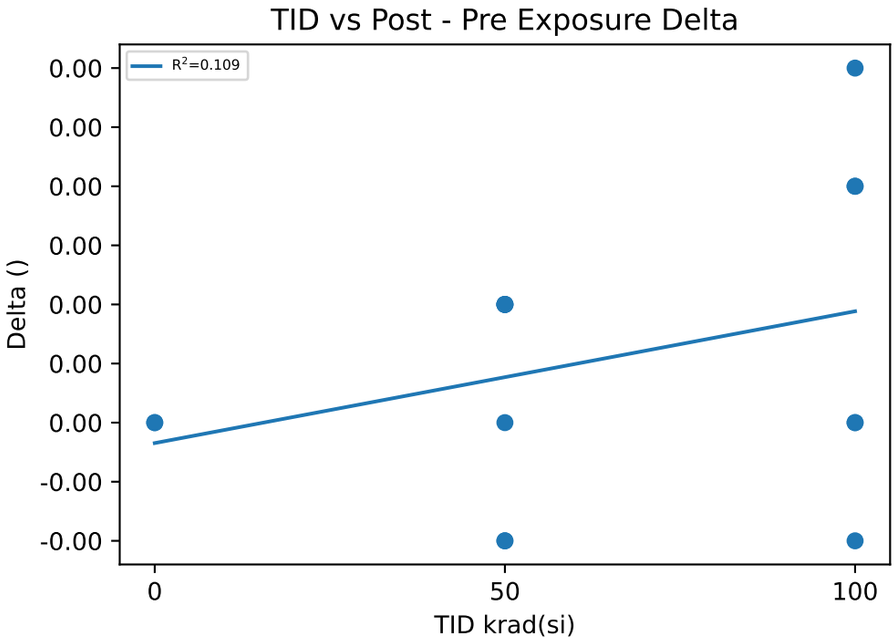
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.742	0.71	-0.032
89	50	Biased	0.731	0.709	-0.022
90	50	Biased	0.728	0.702	-0.026
92	50	Biased	0.747	0.728	-0.019
93	50	Unbiased	0.745	0.728	-0.017
94	50	Unbiased	0.734	0.698	-0.036
95	50	Unbiased	0.738	0.707	-0.031
96	100	Biased	0.72	0.688	-0.032
97	100	Biased	0.729	0.7	-0.029
98	100	Biased	0.72	0.687	-0.033
99	100	Unbiased	0.73	0.7	-0.03
100	100	Unbiased	0.747	0.707	-0.04
101	100	Unbiased	0.727	0.692	-0.035
102	0	Correlation	0.717	0.719	0.002
103	0	Correlation	0.747	0.749	0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.717	0.732	0.747	0.021213	0.719	0.734	0.749	0.021213	0.002	0.002	0.002	0
50	0.728	0.73786	0.747	0.0071979	0.698	0.71171	0.728	0.01187	-0.036	-0.026143	-0.017	0.0071514
100	0.72	0.72883	0.747	0.0099079	0.687	0.69567	0.707	0.0079162	-0.04	-0.033167	-0.029	0.0039707

Device Test: 5.40 WD_TMR_10KOHM(twd_Res10p5K_WDOB_SU/WDOB/1.6/14/10.5K/0/0/@WD_TMR_10KOHM)





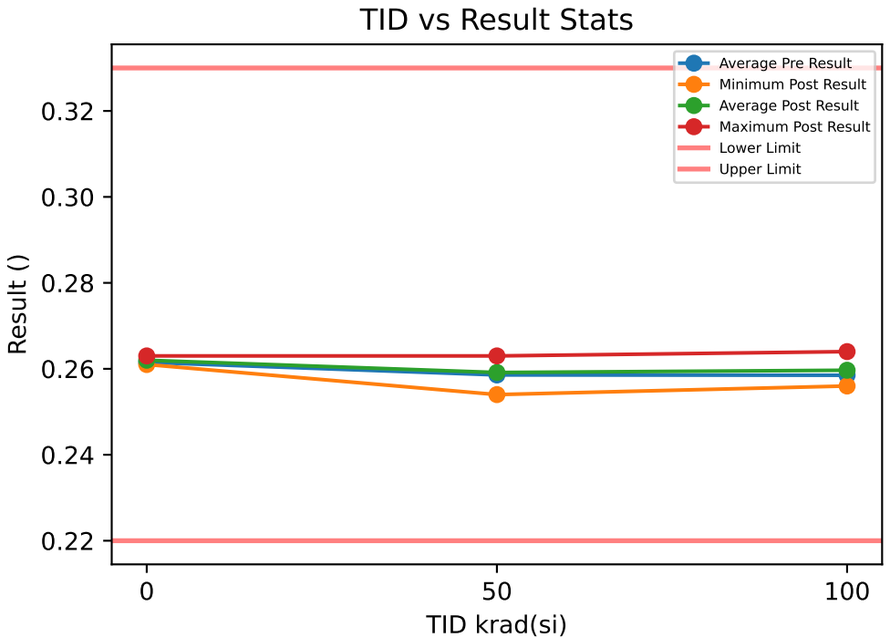
Test Results (Lower Limit = 0.43, Upper Limit = 0.57 ())

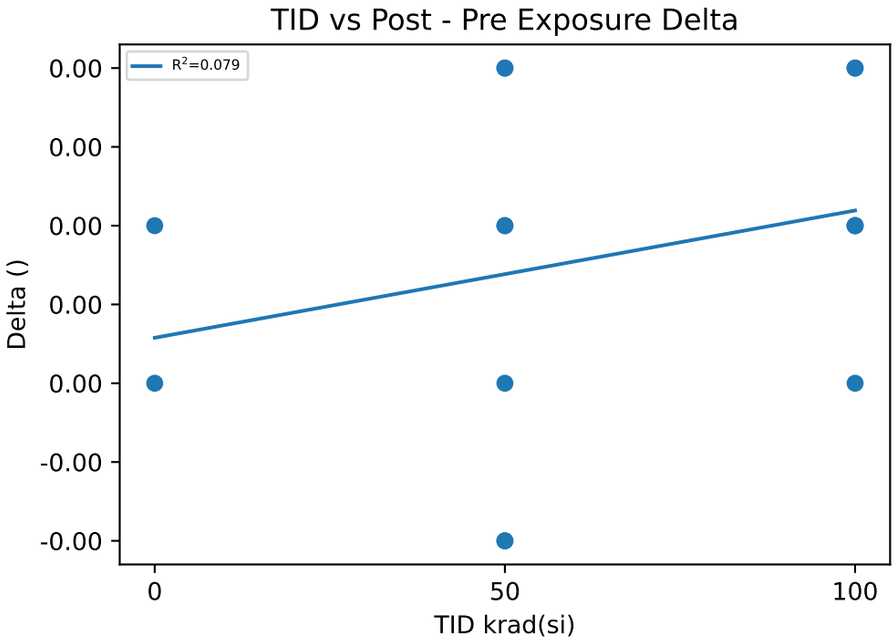
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.517	0.516	-0.001
89	50	Biased	0.51	0.511	0.001
90	50	Biased	0.512	0.513	0.001
92	50	Biased	0.519	0.52	0.001
93	50	Unbiased	0.512	0.513	0.001
94	50	Unbiased	0.524	0.524	0
95	50	Unbiased	0.519	0.518	-0.001
96	100	Biased	0.516	0.515	-0.001
97	100	Biased	0.52	0.52	0
98	100	Biased	0.513	0.513	0
99	100	Unbiased	0.519	0.522	0.003
100	100	Unbiased	0.515	0.517	0.002
101	100	Unbiased	0.519	0.521	0.002
102	0	Correlation	0.525	0.525	0
103	0	Correlation	0.515	0.515	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.515	0.52	0.525	0.0070711	0.515	0.52	0.525	0.0070711	0	0	0	0
50	0.51	0.51614	0.524	0.0050143	0.511	0.51643	0.524	0.0045774	-0.001	0.00028571	0.001	0.00095119
100	0.513	0.517	0.52	0.0027568	0.513	0.518	0.522	0.0035777	-0.001	0.001	0.003	0.0015492

Device Test: 5.41 DLY_TMR_10KOHM(tdly_Res10p5K_PWRGD_SU/PWRGD/1.6/14/10.5K/0/0/@DLY_TMR_10KOHM)





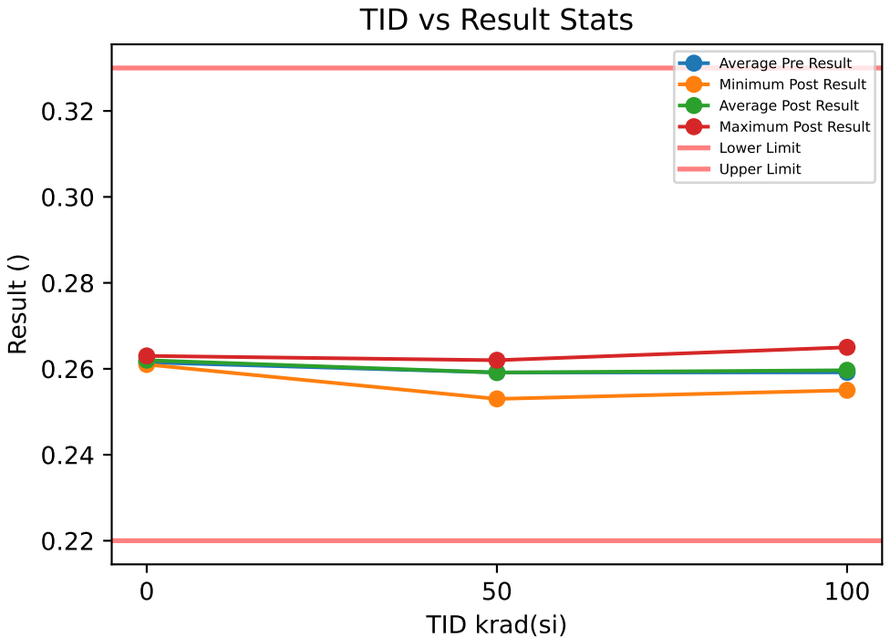
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

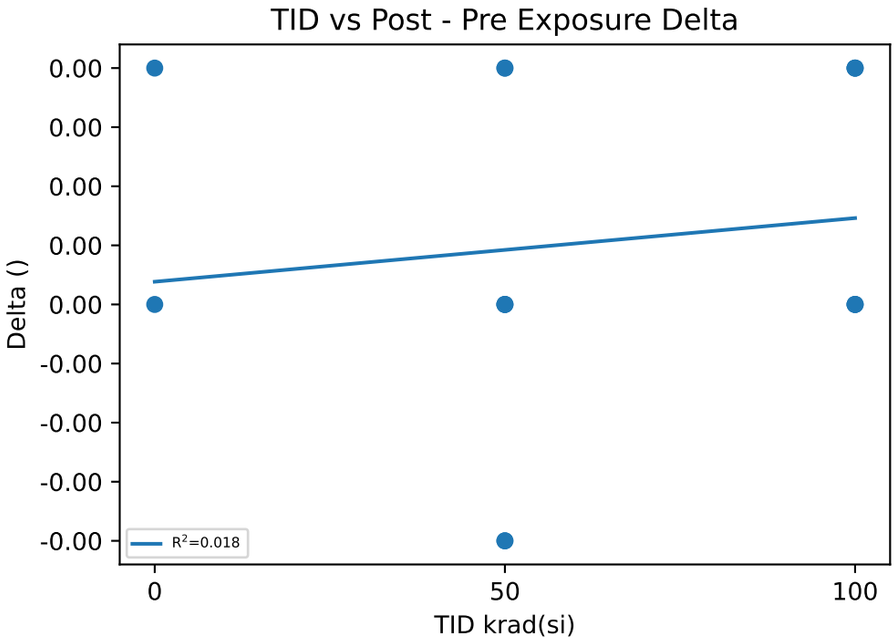
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.262	0.261	-0.001
89	50	Biased	0.26	0.259	-0.001
90	50	Biased	0.252	0.254	0.002
92	50	Biased	0.26	0.262	0.002
93	50	Unbiased	0.253	0.254	0.001
94	50	Unbiased	0.263	0.263	0
95	50	Unbiased	0.26	0.261	0.001
96	100	Biased	0.255	0.256	0.001
97	100	Biased	0.262	0.264	0.002
98	100	Biased	0.261	0.261	0
99	100	Unbiased	0.256	0.257	0.001
100	100	Unbiased	0.255	0.256	0.001
101	100	Unbiased	0.262	0.264	0.002
102	0	Correlation	0.262	0.263	0.001
103	0	Correlation	0.261	0.261	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.261	0.2615	0.262	0.00070711	0.261	0.262	0.263	0.0014142	0	0.0005	0.001	0.00070711
50	0.252	0.25857	0.263	0.004315	0.254	0.25914	0.263	0.0037161	-0.001	0.00057143	0.002	0.0012724
100	0.255	0.2585	0.262	0.0035071	0.256	0.25967	0.264	0.0038297	0	0.0011667	0.002	0.00075277

Device Test: 5.42 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB2_SD/RESETB2/1.6/14/10.5K/0/0/@DLY_TMR_10KOHM





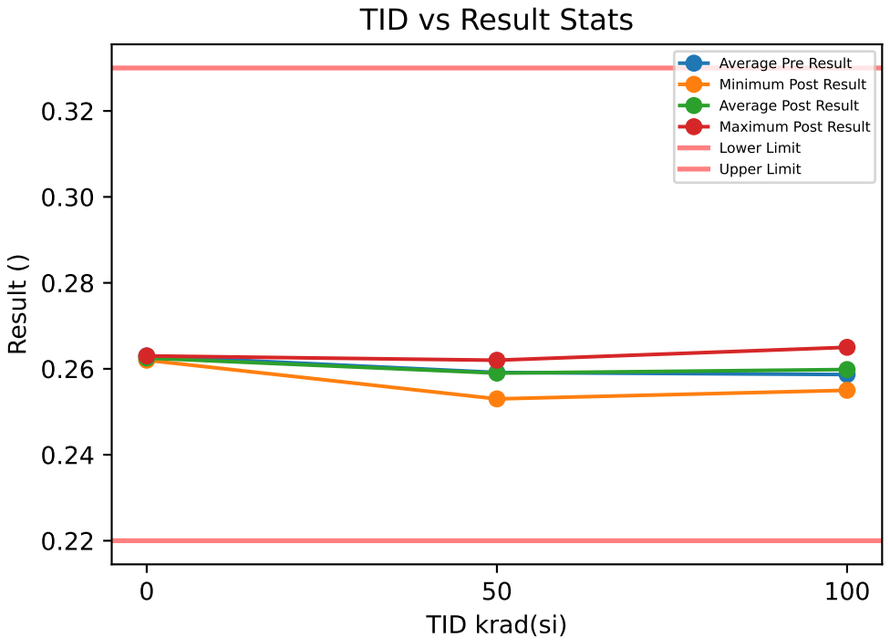
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

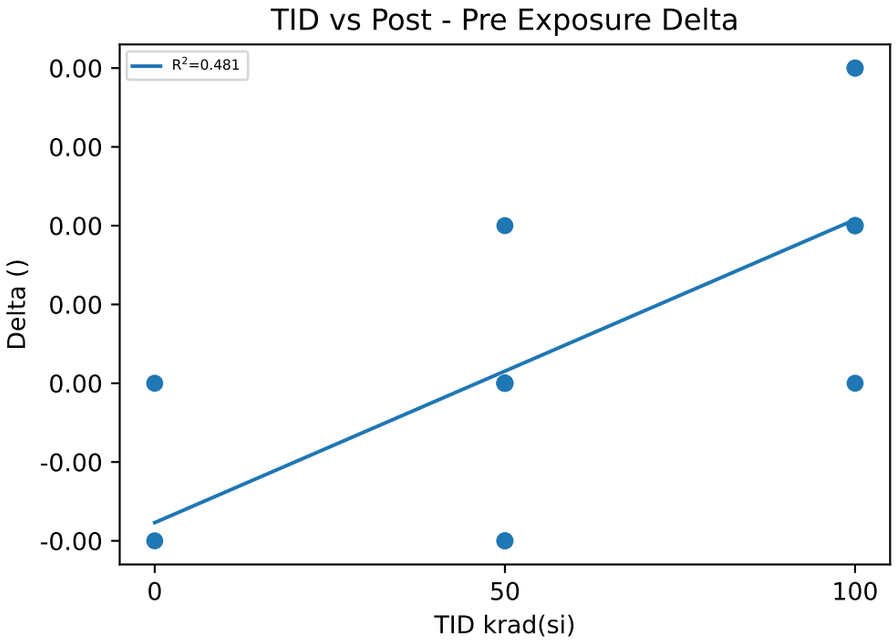
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.262	0.261	-0.001
89	50	Biased	0.261	0.261	0
90	50	Biased	0.254	0.253	-0.001
92	50	Biased	0.261	0.261	0
93	50	Unbiased	0.253	0.254	0.001
94	50	Unbiased	0.262	0.262	0
95	50	Unbiased	0.261	0.262	0.001
96	100	Biased	0.255	0.255	0
97	100	Biased	0.264	0.265	0.001
98	100	Biased	0.262	0.262	0
99	100	Unbiased	0.256	0.257	0.001
100	100	Unbiased	0.256	0.256	0
101	100	Unbiased	0.262	0.263	0.001
102	0	Correlation	0.262	0.263	0.001
103	0	Correlation	0.261	0.261	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.261	0.2615	0.262	0.00070711	0.261	0.262	0.263	0.0014142	0	0.0005	0.001	0.00070711
50	0.253	0.25914	0.262	0.0038914	0.253	0.25914	0.262	0.0038914	-0.001	0	0.001	0.0008165
100	0.255	0.25917	0.264	0.00392	0.255	0.25967	0.265	0.0041793	0	0.0005	0.001	0.00054772

Device Test: 5.43 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB4_SD/RESETB4/1.6/14/10.5K/0/0/@DLY_TMR_10KOHM





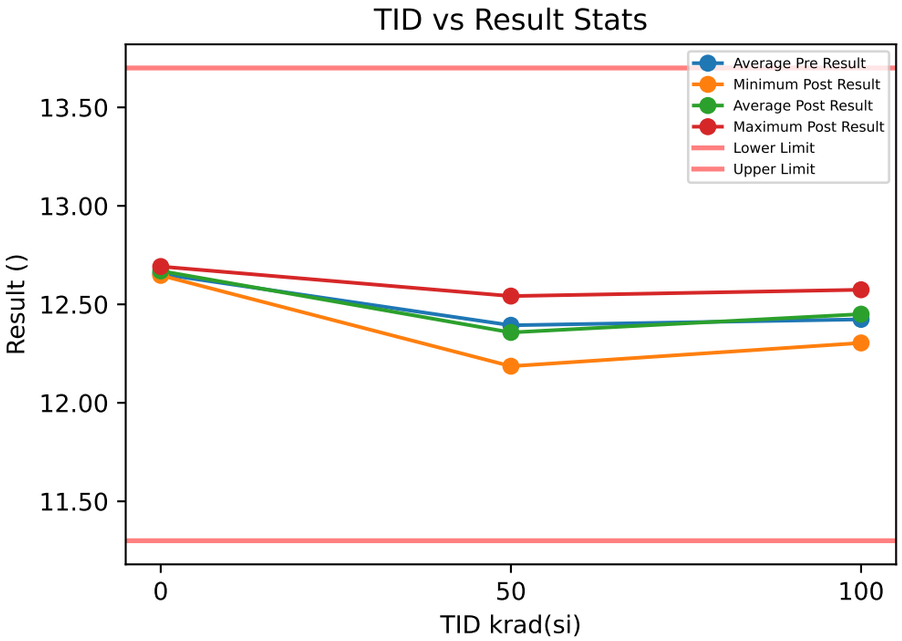
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

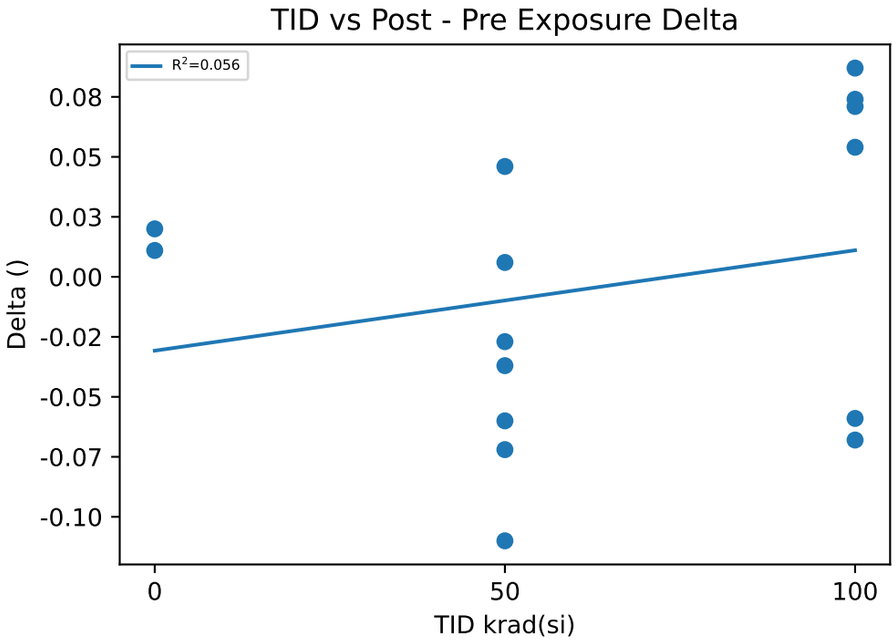
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.261	0.261	0
89	50	Biased	0.261	0.261	0
90	50	Biased	0.254	0.253	-0.001
92	50	Biased	0.262	0.261	-0.001
93	50	Unbiased	0.253	0.253	0
94	50	Unbiased	0.262	0.262	0
95	50	Unbiased	0.261	0.262	0.001
96	100	Biased	0.255	0.257	0.002
97	100	Biased	0.264	0.265	0.001
98	100	Biased	0.26	0.261	0.001
99	100	Unbiased	0.257	0.257	0
100	100	Unbiased	0.254	0.255	0.001
101	100	Unbiased	0.262	0.264	0.002
102	0	Correlation	0.264	0.263	-0.001
103	0	Correlation	0.262	0.262	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.262	0.263	0.264	0.0014142	0.262	0.2625	0.263	0.00070711	-0.001	-0.0005	0	0.00070711
50	0.253	0.25914	0.262	0.0038914	0.253	0.259	0.262	0.0041231	-0.001	-0.00014286	0.001	0.00069007
100	0.254	0.25867	0.264	0.0039833	0.255	0.25983	0.265	0.0041191	0	0.0011667	0.002	0.00075277

Device Test: 5.44 DLY_TMR_500KOHM(tdly_Res619K_RESETB1_SU/RESETB1/1.6/14/619K/0/0/@DLY_TMR_500KOHM





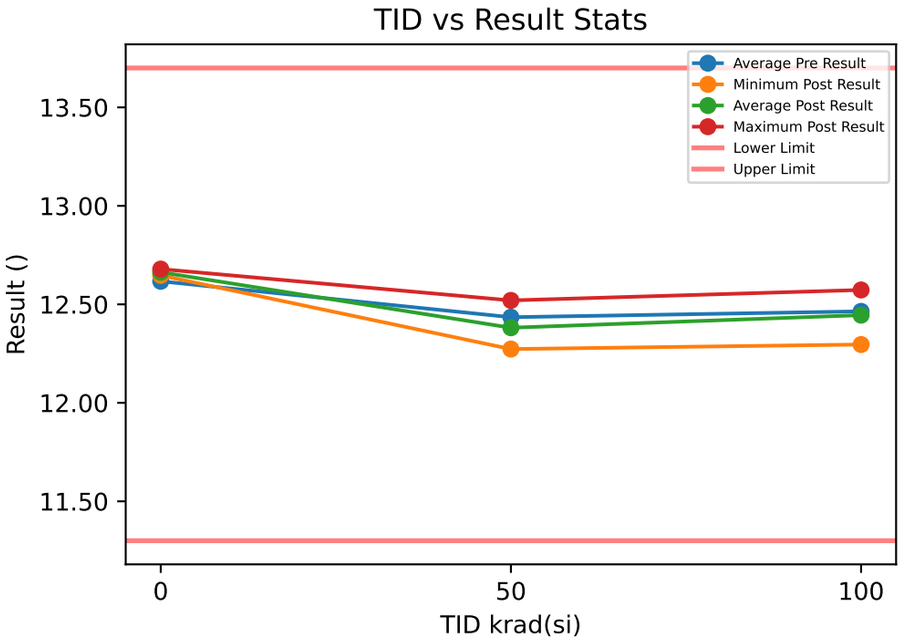
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

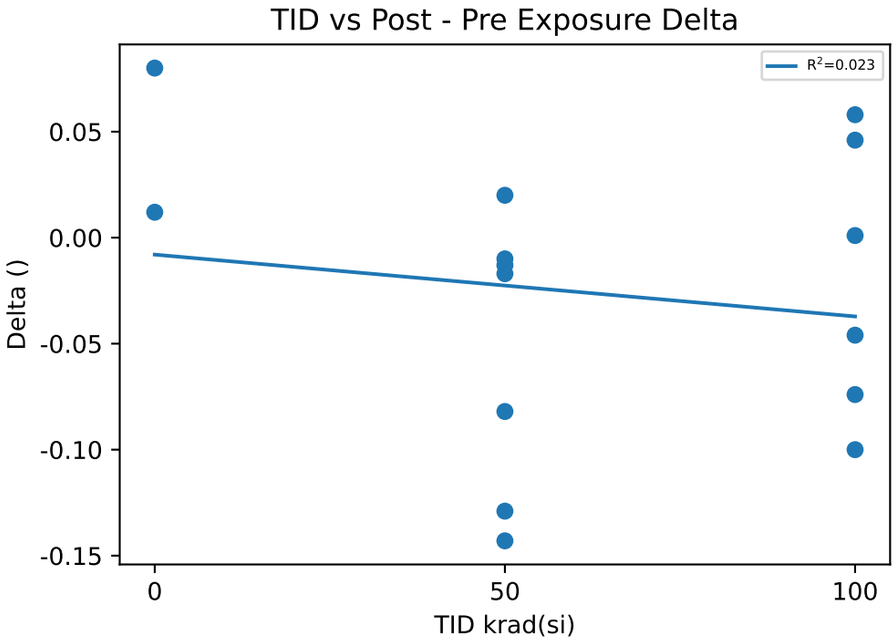
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.443	12.406	-0.037
89	50	Biased	12.496	12.542	0.046
90	50	Biased	12.382	12.272	-0.11
92	50	Biased	12.395	12.335	-0.06
93	50	Unbiased	12.258	12.186	-0.072
94	50	Unbiased	12.41	12.416	0.006
95	50	Unbiased	12.372	12.345	-0.027
96	100	Biased	12.397	12.329	-0.068
97	100	Biased	12.444	12.531	0.087
98	100	Biased	12.39	12.444	0.054
99	100	Unbiased	12.503	12.574	0.071
100	100	Unbiased	12.363	12.304	-0.059
101	100	Unbiased	12.445	12.519	0.074
102	0	Correlation	12.627	12.647	0.02
103	0	Correlation	12.681	12.692	0.011

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.627	12.654	12.681	0.038184	12.647	12.669	12.692	0.03182	0.011	0.0155	0.02	0.006364
50	12.258	12.394	12.496	0.073241	12.186	12.357	12.542	0.11343	-0.11	-0.036286	0.046	0.051506
100	12.363	12.424	12.503	0.050373	12.304	12.45	12.574	0.11197	-0.068	0.0265	0.087	0.07056

Device Test: 5.45 DLY_TMR_500KOHM(tdly_Res619K_RESETB3_SU/RESETB3/1.6/14/619K/0/0/@DLY_TMR_500KOHM





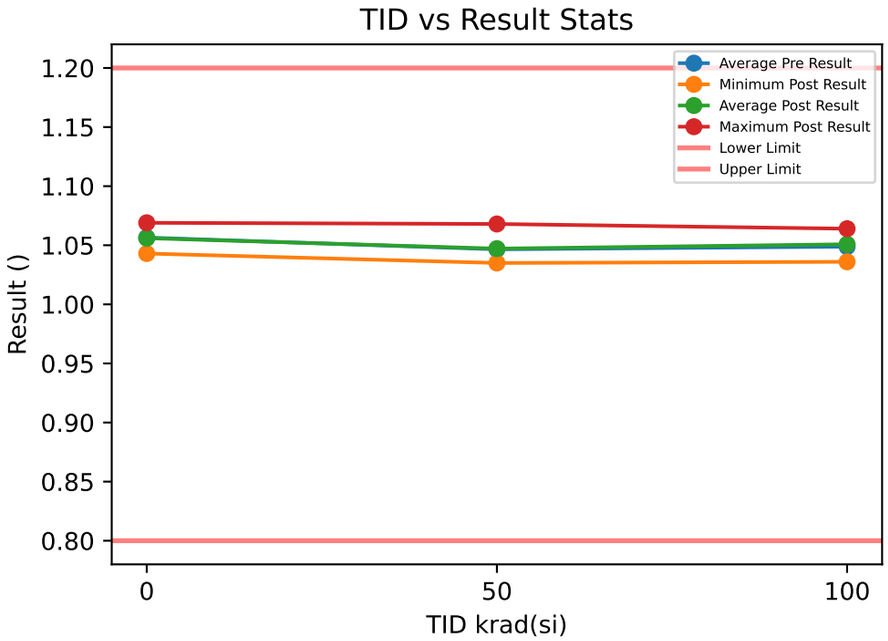
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

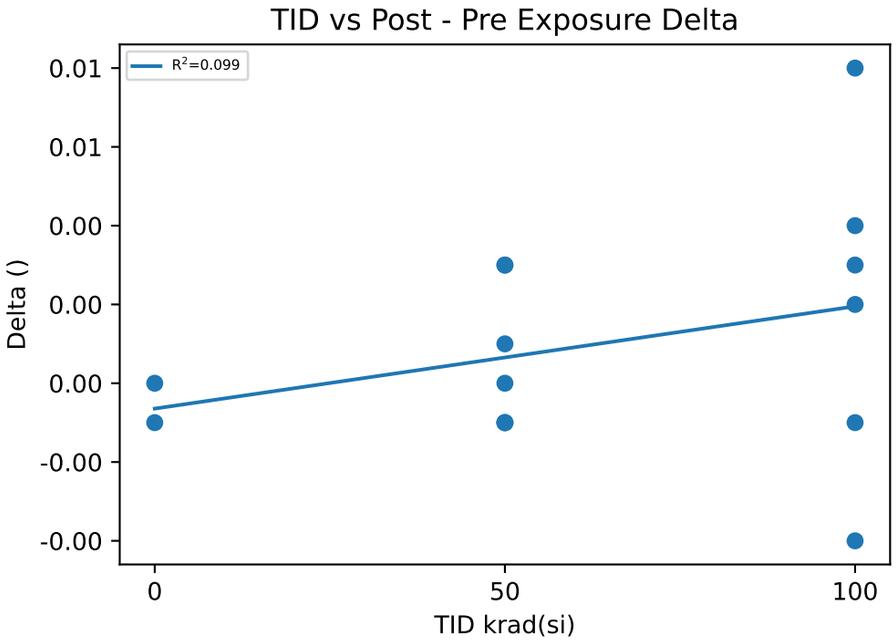
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.513	12.384	-0.129
89	50	Biased	12.537	12.52	-0.017
90	50	Biased	12.378	12.365	-0.013
92	50	Biased	12.468	12.325	-0.143
93	50	Unbiased	12.253	12.273	0.02
94	50	Unbiased	12.473	12.463	-0.01
95	50	Unbiased	12.421	12.339	-0.082
96	100	Biased	12.394	12.32	-0.074
97	100	Biased	12.51	12.511	0.001
98	100	Biased	12.465	12.419	-0.046
99	100	Unbiased	12.506	12.552	0.046
100	100	Unbiased	12.396	12.296	-0.1
101	100	Unbiased	12.515	12.573	0.058
102	0	Correlation	12.599	12.679	0.08
103	0	Correlation	12.635	12.647	0.012

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.599	12.617	12.635	0.025456	12.647	12.663	12.679	0.022627	0.012	0.046	0.08	0.048083
50	12.253	12.435	12.537	0.096254	12.273	12.381	12.52	0.084531	-0.143	-0.053429	0.02	0.064278
100	12.394	12.464	12.515	0.056578	12.296	12.445	12.573	0.1189	-0.1	-0.019167	0.058	0.064605

Device Test: 5.46 WD_TMR_500KOHM(twd_Res619K_WDOB_SU/WDOB/1.6/14/619K/0/0/@WD_TMR_500KOHM)





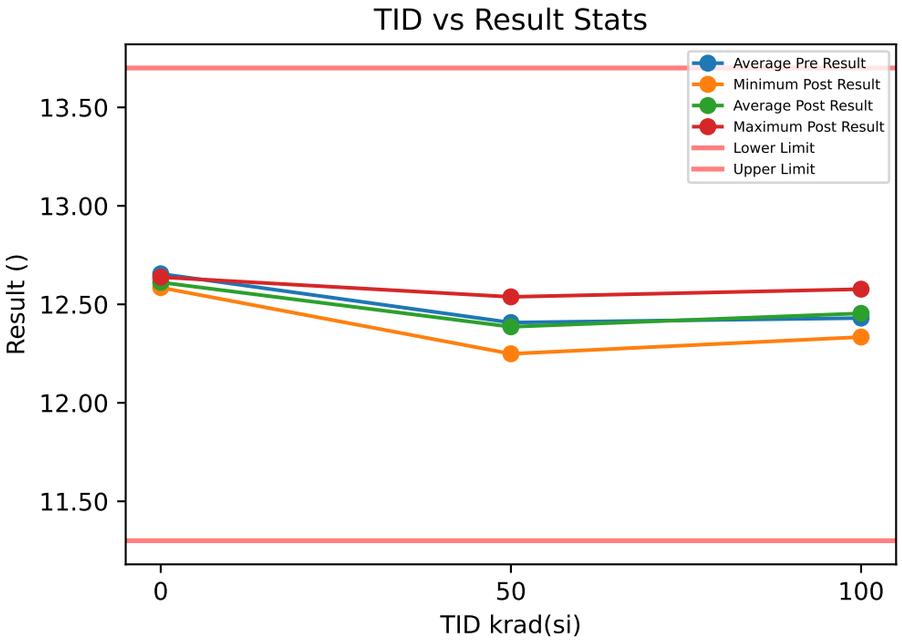
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 ())

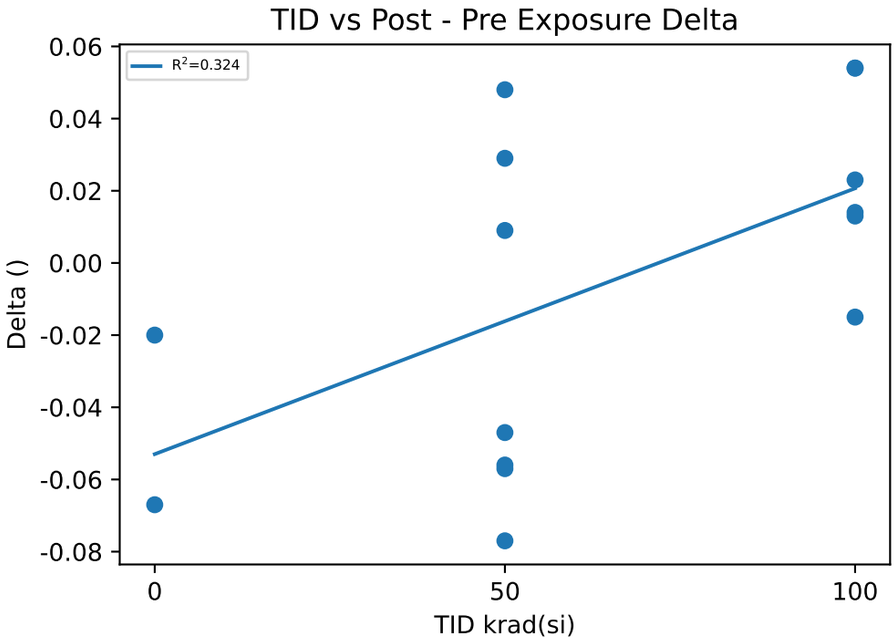
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.047	1.046	-0.001
89	50	Biased	1.032	1.035	0.003
90	50	Biased	1.035	1.036	0.001
92	50	Biased	1.056	1.056	0
93	50	Unbiased	1.034	1.037	0.003
94	50	Unbiased	1.069	1.068	-0.001
95	50	Unbiased	1.053	1.052	-0.001
96	100	Biased	1.047	1.043	-0.004
97	100	Biased	1.054	1.056	0.002
98	100	Biased	1.037	1.036	-0.001
99	100	Unbiased	1.056	1.064	0.008
100	100	Unbiased	1.043	1.046	0.003
101	100	Unbiased	1.056	1.06	0.004
102	0	Correlation	1.07	1.069	-0.001
103	0	Correlation	1.043	1.043	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.043	1.0565	1.07	0.019092	1.043	1.056	1.069	0.018385	-0.001	-0.0005	0	0.00070711
50	1.032	1.0466	1.069	0.01377	1.035	1.0471	1.068	0.012335	-0.001	0.00057143	0.003	0.0018127
100	1.037	1.0488	1.056	0.0078337	1.036	1.0508	1.064	0.010852	-0.004	0.002	0.008	0.0041473

Device Test: 5.47 DLY_TMR_500KOHM(tdly_Res619K_PWRGD_SU/PWRGD/1.6/14/619K/0/0/@DLY_TMR_500KOHM)





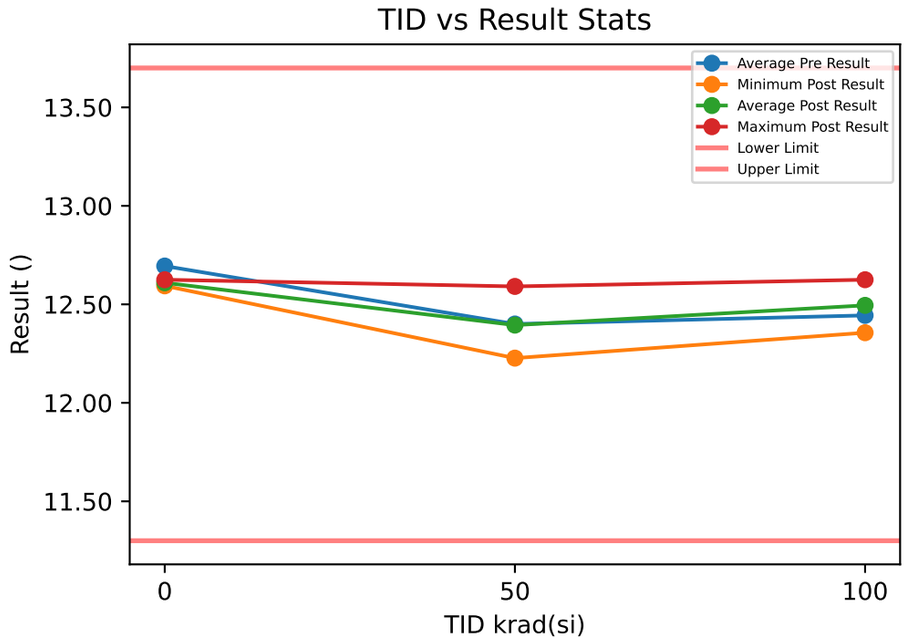
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

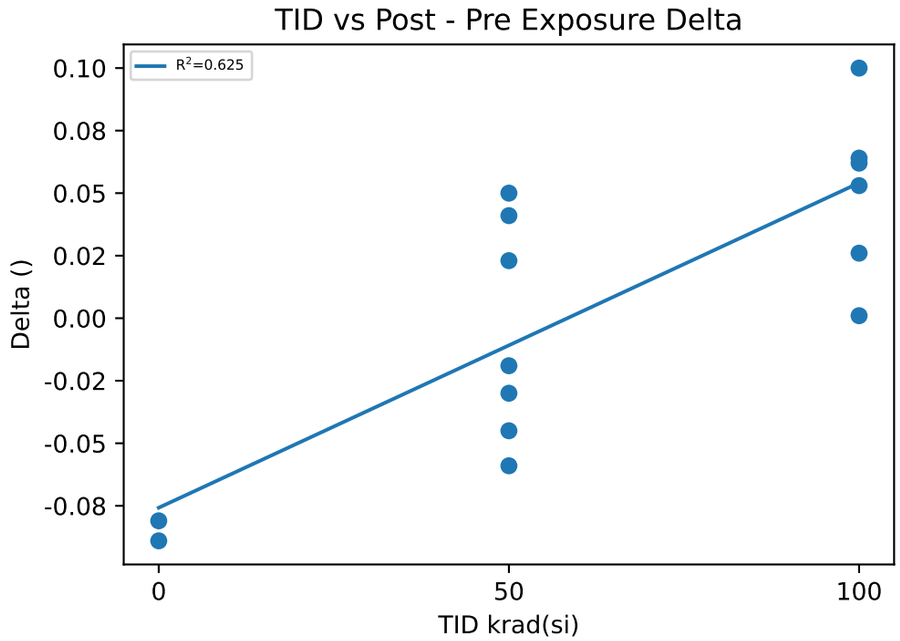
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.437	12.466	0.029
89	50	Biased	12.49	12.538	0.048
90	50	Biased	12.378	12.301	-0.077
92	50	Biased	12.444	12.387	-0.057
93	50	Unbiased	12.24	12.249	0.009
94	50	Unbiased	12.446	12.399	-0.047
95	50	Unbiased	12.418	12.362	-0.056
96	100	Biased	12.359	12.344	-0.015
97	100	Biased	12.466	12.52	0.054
98	100	Biased	12.427	12.441	0.014
99	100	Unbiased	12.523	12.577	0.054
100	100	Unbiased	12.311	12.334	0.023
101	100	Unbiased	12.496	12.509	0.013
102	0	Correlation	12.605	12.585	-0.02
103	0	Correlation	12.705	12.638	-0.067

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.605	12.655	12.705	0.070711	12.585	12.611	12.638	0.037477	-0.067	-0.0435	-0.02	0.033234
50	12.24	12.408	12.49	0.081166	12.249	12.386	12.538	0.096819	-0.077	-0.021571	0.048	0.049146
100	12.311	12.43	12.523	0.081867	12.334	12.454	12.577	0.099175	-0.015	0.023833	0.054	0.026619

Device Test: 5.48 DLY_TMR_500KOHM(tdly_Res619K_RESETB2_SD/RESETB2/1.6/14/619K/0/0/@DLY_TMR_500KOHM





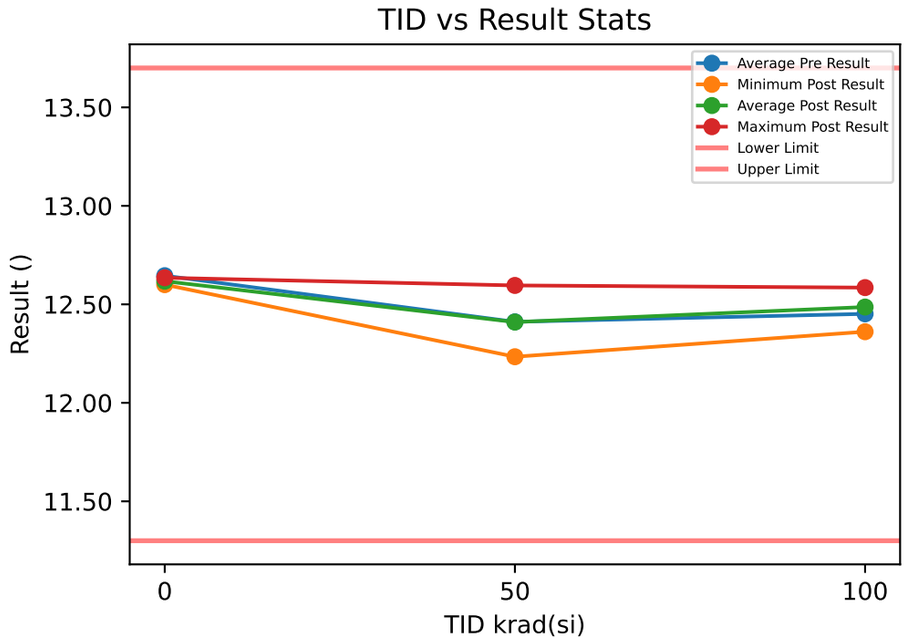
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

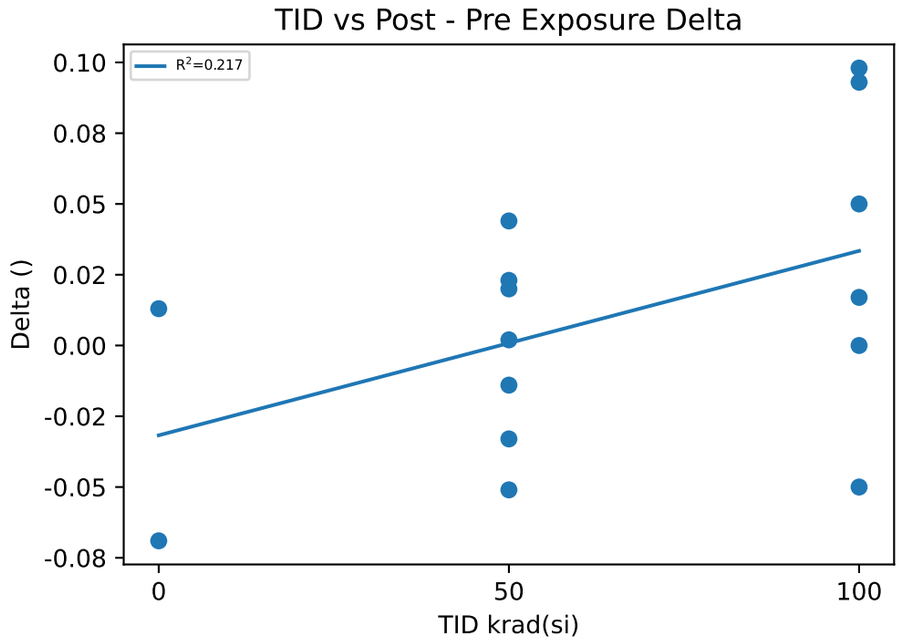
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.48	12.421	-0.059
89	50	Biased	12.541	12.591	0.05
90	50	Biased	12.338	12.308	-0.03
92	50	Biased	12.43	12.385	-0.045
93	50	Unbiased	12.186	12.227	0.041
94	50	Unbiased	12.446	12.427	-0.019
95	50	Unbiased	12.38	12.403	0.023
96	100	Biased	12.352	12.378	0.026
97	100	Biased	12.48	12.58	0.1
98	100	Biased	12.43	12.483	0.053
99	100	Unbiased	12.563	12.625	0.062
100	100	Unbiased	12.355	12.356	0.001
101	100	Unbiased	12.483	12.547	0.064
102	0	Correlation	12.675	12.594	-0.081
103	0	Correlation	12.714	12.625	-0.089

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.675	12.695	12.714	0.027577	12.594	12.61	12.625	0.02192	-0.089	-0.085	-0.081	0.0056569
50	12.186	12.4	12.541	0.11499	12.227	12.395	12.591	0.1126	-0.059	-0.0055714	0.05	0.04332
100	12.352	12.444	12.563	0.081925	12.356	12.495	12.625	0.10953	0.001	0.051	0.1	0.034117

Device Test: 5.49 DLY_TMR_500KOHM(tdly_Res619K_RESETB4_SD/RESETB4/1.6/14/619K/0/0/@DLY_TMR_500KOHM





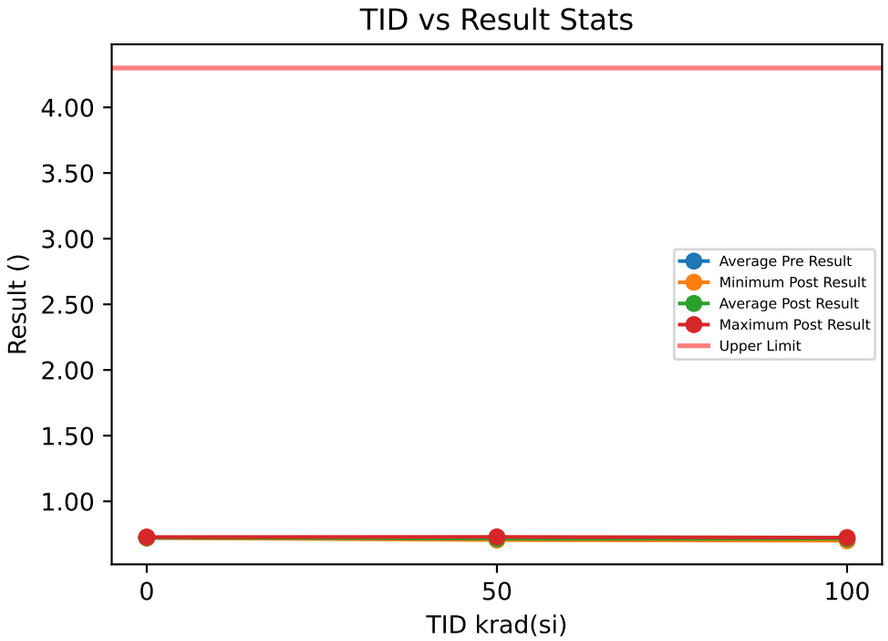
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

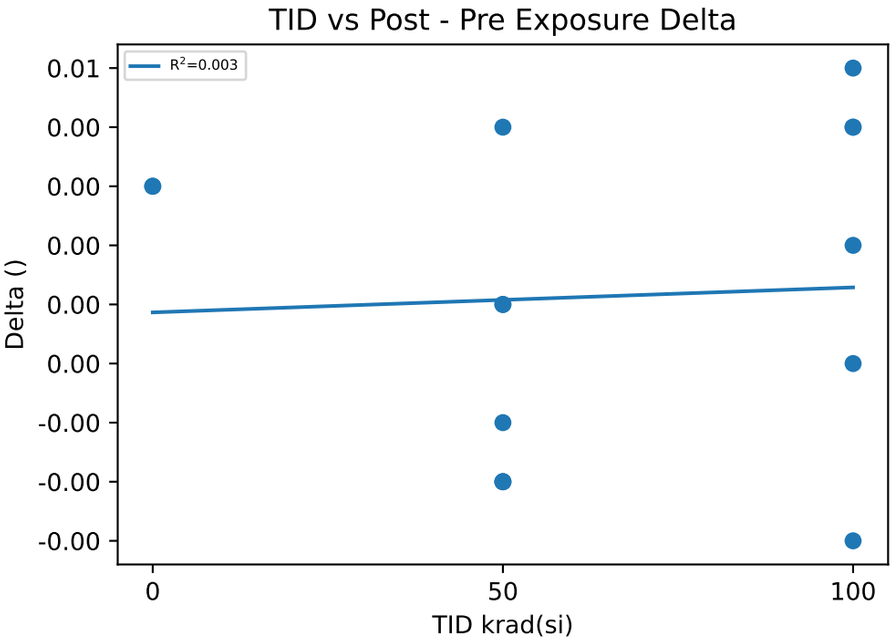
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.487	12.454	-0.033
89	50	Biased	12.552	12.596	0.044
90	50	Biased	12.345	12.331	-0.014
92	50	Biased	12.441	12.39	-0.051
93	50	Unbiased	12.211	12.234	0.023
94	50	Unbiased	12.457	12.459	0.002
95	50	Unbiased	12.386	12.406	0.02
96	100	Biased	12.361	12.378	0.017
97	100	Biased	12.487	12.585	0.098
98	100	Biased	12.438	12.488	0.05
99	100	Unbiased	12.583	12.533	-0.05
100	100	Unbiased	12.361	12.361	0
101	100	Unbiased	12.48	12.573	0.093
102	0	Correlation	12.669	12.6	-0.069
103	0	Correlation	12.622	12.635	0.013

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.622	12.646	12.669	0.033234	12.6	12.617	12.635	0.024749	-0.069	-0.028	0.013	0.057983
50	12.211	12.411	12.552	0.1108	12.234	12.41	12.596	0.11296	-0.051	-0.0012857	0.044	0.033525
100	12.361	12.452	12.583	0.084767	12.361	12.486	12.585	0.096821	-0.05	0.034667	0.098	0.057151

Device Test: 5.5 PROPD_RESET(tpd_RESETB1_SU/RESETB1/1.6/14/0/0/0/@PROPD_RESET)





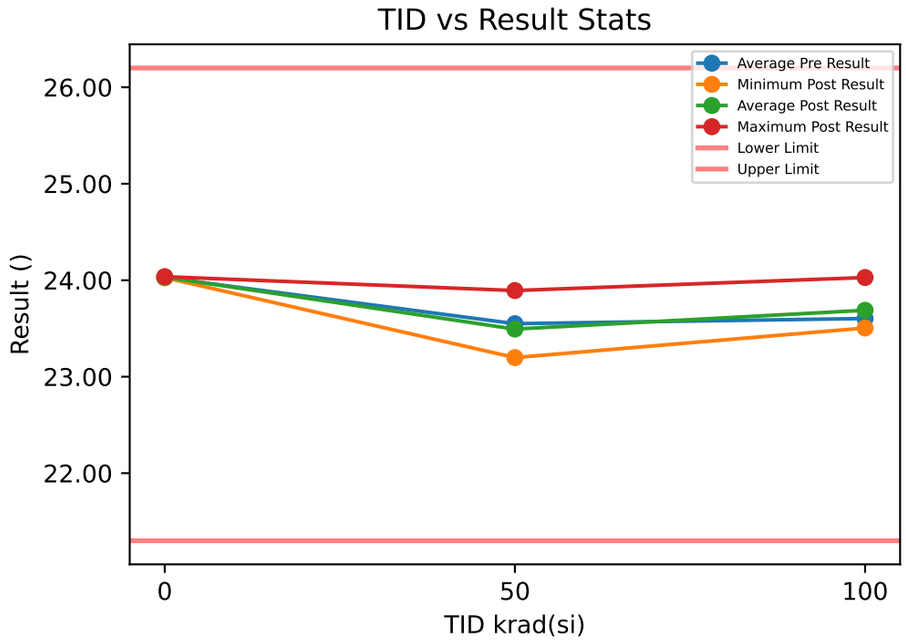
Test Results (Upper Limit = 4.3 ())

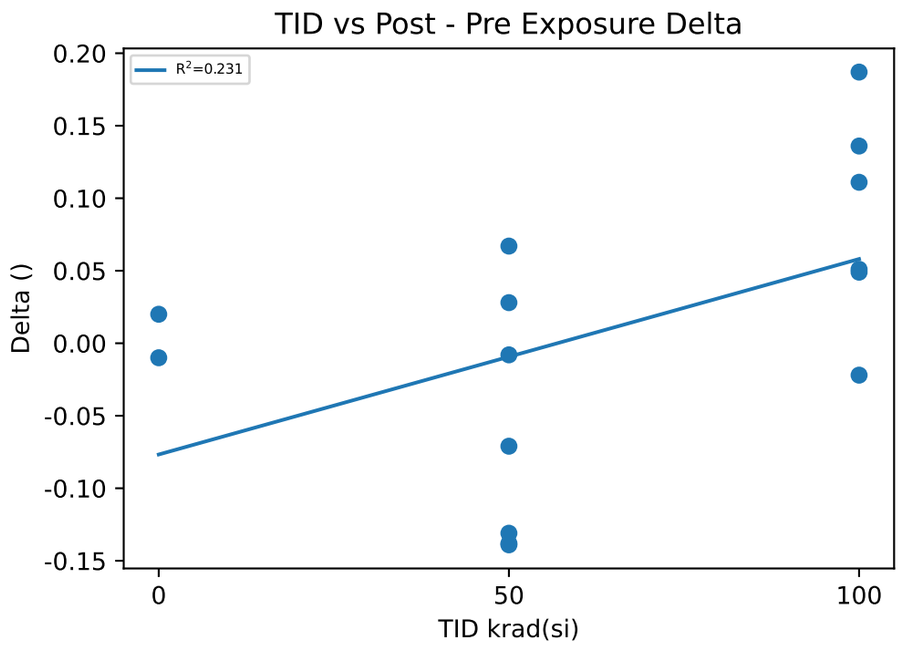
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.713	0.714	0.001
89	50	Biased	0.707	0.706	-0.001
90	50	Biased	0.704	0.705	0.001
92	50	Biased	0.707	0.711	0.004
93	50	Unbiased	0.725	0.723	-0.002
94	50	Unbiased	0.731	0.729	-0.002
95	50	Unbiased	0.722	0.72	-0.002
96	100	Biased	0.704	0.706	0.002
97	100	Biased	0.72	0.724	0.004
98	100	Biased	0.713	0.718	0.005
99	100	Unbiased	0.718	0.722	0.004
100	100	Unbiased	0.721	0.721	0
101	100	Unbiased	0.703	0.7	-0.003
102	0	Correlation	0.718	0.721	0.003
103	0	Correlation	0.725	0.728	0.003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.718	0.7215	0.725	0.0049497	0.721	0.7245	0.728	0.0049497	0.003	0.003	0.003	0
50	0.704	0.71557	0.731	0.010454	0.705	0.71543	0.729	0.0089602	-0.002	-0.00014286	0.004	0.0022678
100	0.703	0.71317	0.721	0.0079854	0.7	0.71517	0.724	0.0098065	-0.003	0.002	0.005	0.0030332

Device Test: 5.50 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB1_SU/RESETB1/1.6/14/1.18M/0/0/@DLY_TMR_1MOHM)





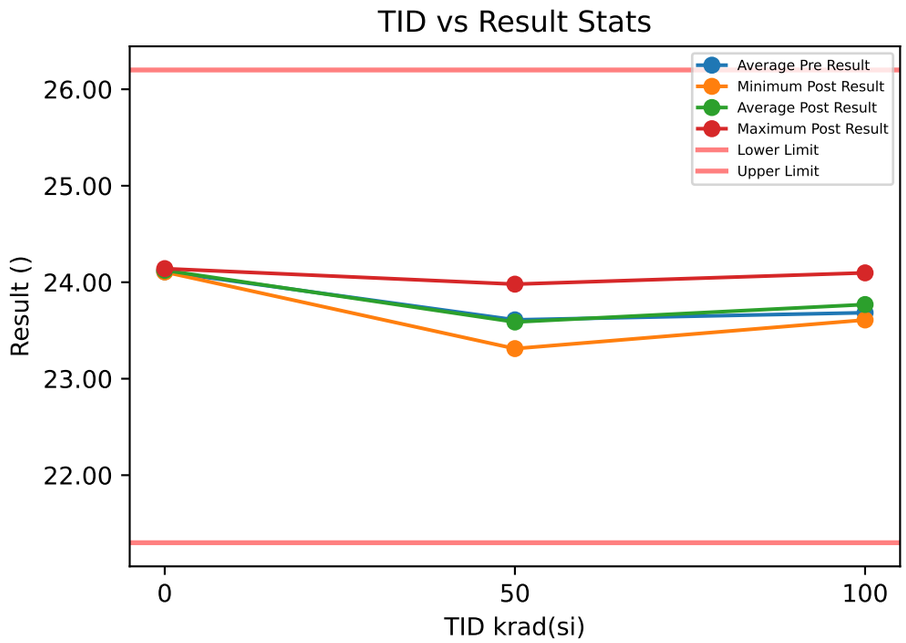
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

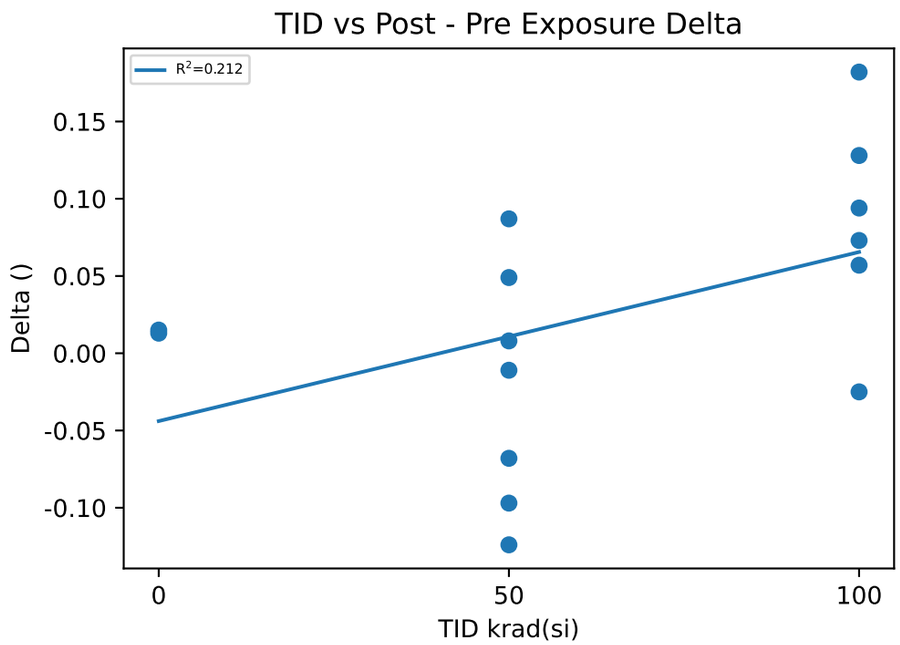
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.598	23.459	-0.139
89	50	Biased	23.826	23.893	0.067
90	50	Biased	23.581	23.51	-0.071
92	50	Biased	23.562	23.431	-0.131
93	50	Unbiased	23.336	23.198	-0.138
94	50	Unbiased	23.53	23.522	-0.008
95	50	Unbiased	23.414	23.442	0.028
96	100	Biased	23.527	23.576	0.049
97	100	Biased	23.569	23.756	0.187
98	100	Biased	23.454	23.505	0.051
99	100	Unbiased	23.917	24.028	0.111
100	100	Unbiased	23.553	23.531	-0.022
101	100	Unbiased	23.599	23.735	0.136
102	0	Correlation	24.007	24.027	0.02
103	0	Correlation	24.047	24.037	-0.01

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.007	24.027	24.047	0.028284	24.027	24.032	24.037	0.0070711	-0.01	0.005	0.02	0.021213
50	23.336	23.55	23.826	0.15507	23.198	23.494	23.893	0.20646	-0.139	-0.056	0.067	0.085588
100	23.454	23.603	23.917	0.1614	23.505	23.689	24.028	0.19653	-0.022	0.085333	0.187	0.074272

Device Test: 5.51 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB3_SU/RESETB3/1.6/14/1.18M/0/0/@DLY_TMR_1MOHM)





Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

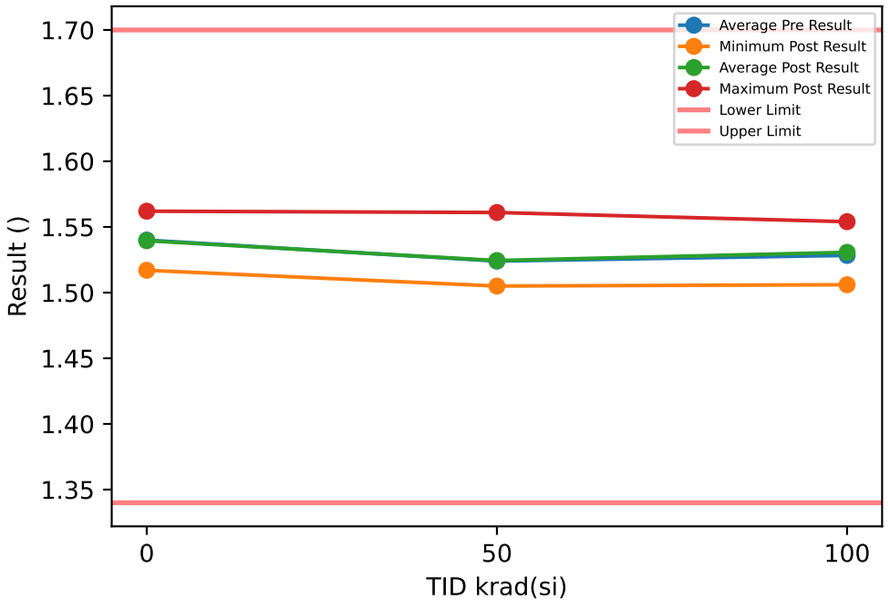
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.676	23.579	-0.097
89	50	Biased	23.893	23.98	0.087
90	50	Biased	23.658	23.59	-0.068
92	50	Biased	23.653	23.529	-0.124
93	50	Unbiased	23.263	23.312	0.049
94	50	Unbiased	23.611	23.6	-0.011
95	50	Unbiased	23.516	23.524	0.008
96	100	Biased	23.608	23.665	0.057
97	100	Biased	23.647	23.829	0.182
98	100	Biased	23.536	23.609	0.073
99	100	Unbiased	24.003	24.097	0.094
100	100	Unbiased	23.634	23.609	-0.025
101	100	Unbiased	23.676	23.804	0.128
102	0	Correlation	24.091	24.106	0.015
103	0	Correlation	24.128	24.141	0.013

Test Statistics ()

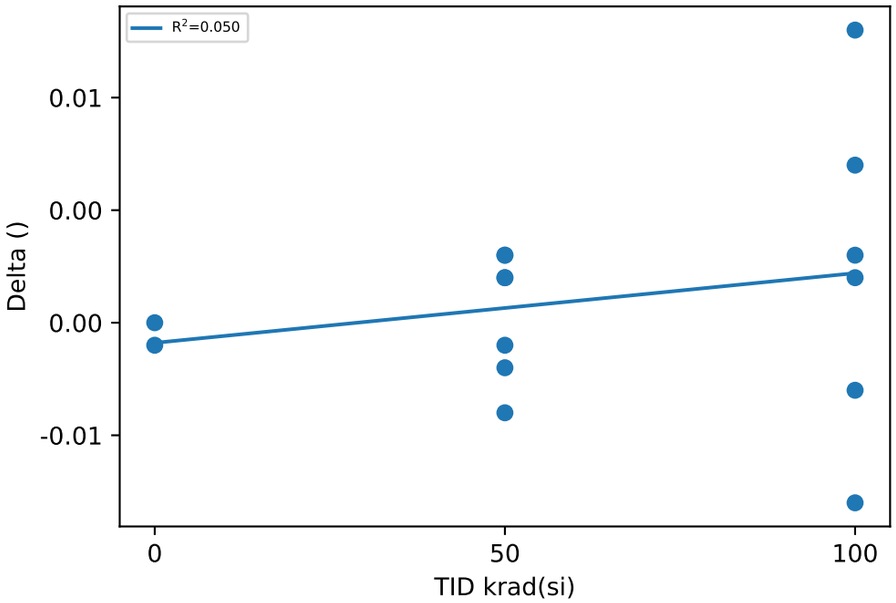
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.091	24.11	24.128	0.026163	24.106	24.123	24.141	0.024749	0.013	0.014	0.015	0.0014142
50	23.263	23.61	23.893	0.19054	23.312	23.588	23.98	0.19902	-0.124	-0.022286	0.087	0.077554
100	23.536	23.684	24.003	0.16332	23.609	23.769	24.097	0.18678	-0.025	0.084833	0.182	0.06981

Device Test: 5.52 WD_TMR_1MOHM(twd_Res1p18M_WDOB_SU/WDOB/1.6/14/1.18M/0/0/@WD_TMR_1MOHM)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



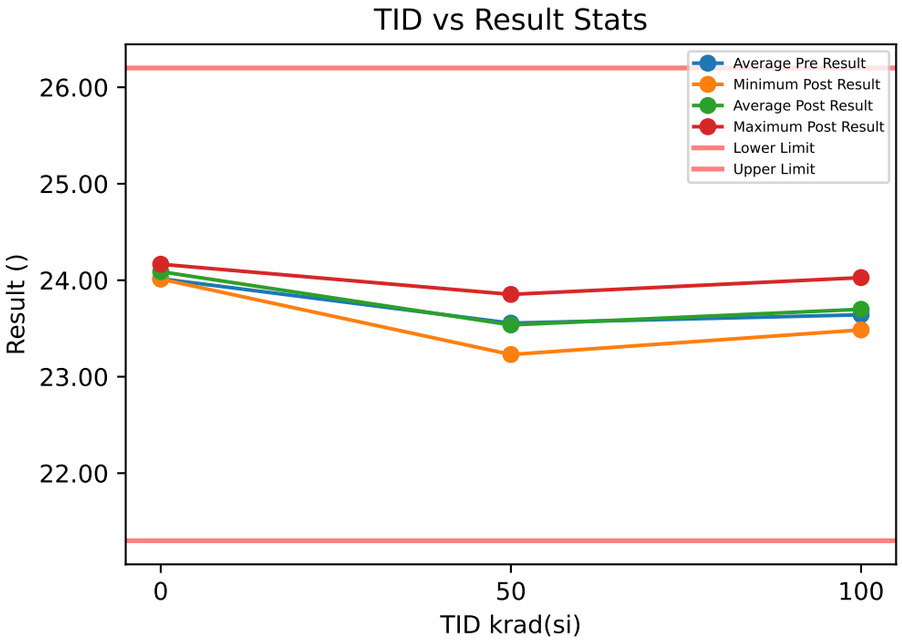
Test Results (Lower Limit = 1.34, Upper Limit = 1.7 ())

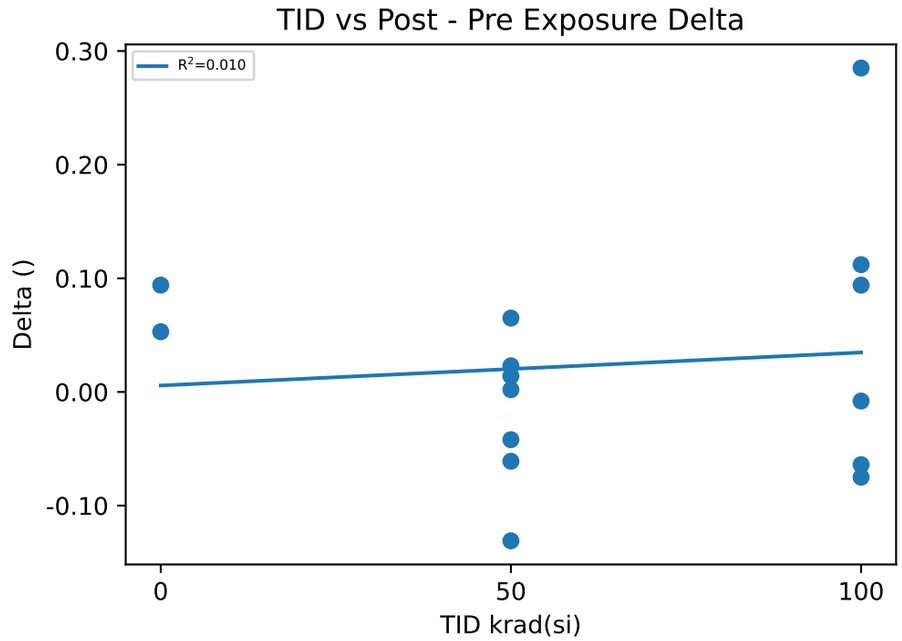
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.525	1.521	-0.004
89	50	Biased	1.502	1.505	0.003
90	50	Biased	1.503	1.505	0.002
92	50	Biased	1.539	1.541	0.002
93	50	Unbiased	1.503	1.506	0.003
94	50	Unbiased	1.562	1.561	-0.001
95	50	Unbiased	1.534	1.532	-0.002
96	100	Biased	1.525	1.517	-0.008
97	100	Biased	1.537	1.539	0.002
98	100	Biased	1.509	1.506	-0.003
99	100	Unbiased	1.541	1.554	0.013
100	100	Unbiased	1.519	1.522	0.003
101	100	Unbiased	1.539	1.546	0.007
102	0	Correlation	1.562	1.562	0
103	0	Correlation	1.518	1.517	-0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.518	1.54	1.562	0.031113	1.517	1.5395	1.562	0.03182	-0.001	-0.0005	0	0.00070711
50	1.502	1.524	1.562	0.022862	1.505	1.5244	1.561	0.021509	-0.004	0.00042857	0.003	0.0027603
100	1.509	1.5283	1.541	0.012817	1.506	1.5307	1.554	0.018544	-0.008	0.0023333	0.013	0.0073666

Device Test: 5.53 DLY_TMR_1MOHM(tdly_Res1p18M_PWRGD_SU/PWRGD/1.6/14/1.18M/0/0/@DLY_TMR_1MOHM)





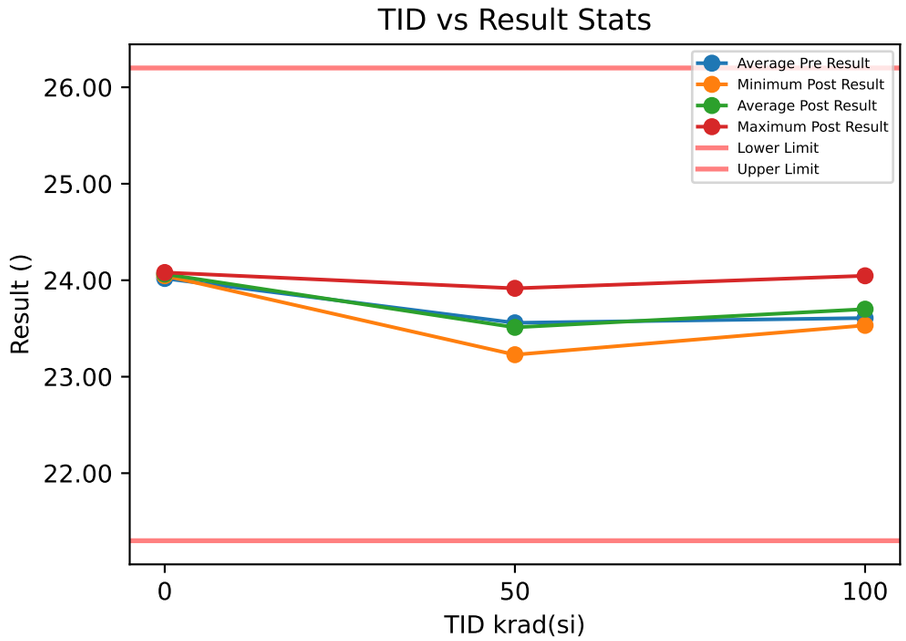
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

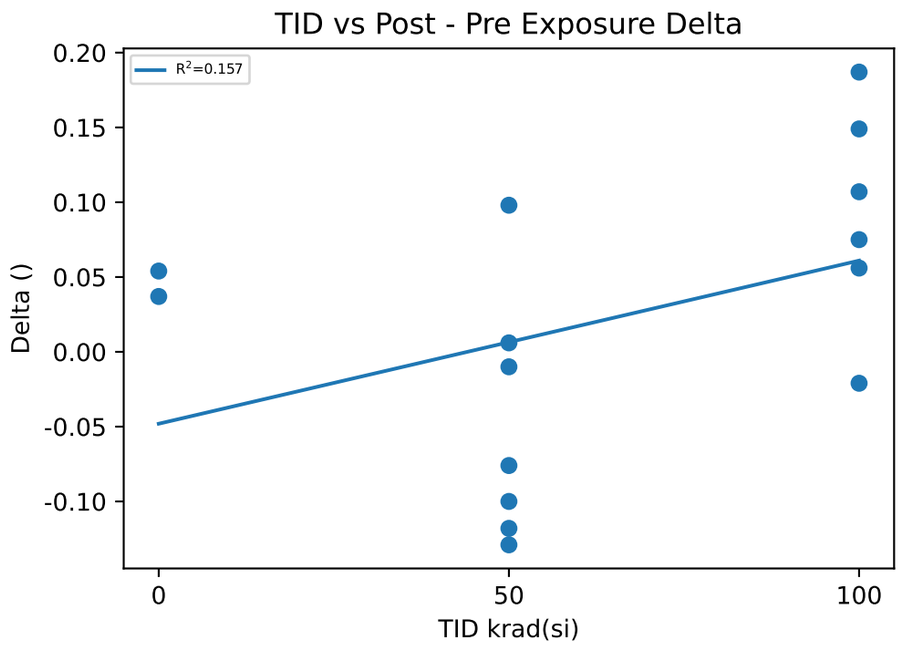
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.562	23.564	0.002
89	50	Biased	23.895	23.853	-0.042
90	50	Biased	23.682	23.551	-0.131
92	50	Biased	23.585	23.524	-0.061
93	50	Unbiased	23.216	23.23	0.014
94	50	Unbiased	23.507	23.53	0.023
95	50	Unbiased	23.44	23.505	0.065
96	100	Biased	23.55	23.542	-0.008
97	100	Biased	23.65	23.762	0.112
98	100	Biased	23.549	23.485	-0.064
99	100	Unbiased	23.933	24.027	0.094
100	100	Unbiased	23.613	23.538	-0.075
101	100	Unbiased	23.555	23.84	0.285
102	0	Correlation	23.959	24.012	0.053
103	0	Correlation	24.072	24.166	0.094

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	23.959	24.015	24.072	0.079903	24.012	24.089	24.166	0.10889	0.053	0.0735	0.094	0.028991
50	23.216	23.555	23.895	0.20941	23.23	23.537	23.853	0.18086	-0.131	-0.018571	0.065	0.064789
100	23.549	23.642	23.933	0.1485	23.485	23.699	24.027	0.21345	-0.075	0.057333	0.285	0.13614

Device Test: 5.54 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB2_SD/RESETB2/1.6/14/1.18M/0/0/@DLY_TMR_1MOHM)





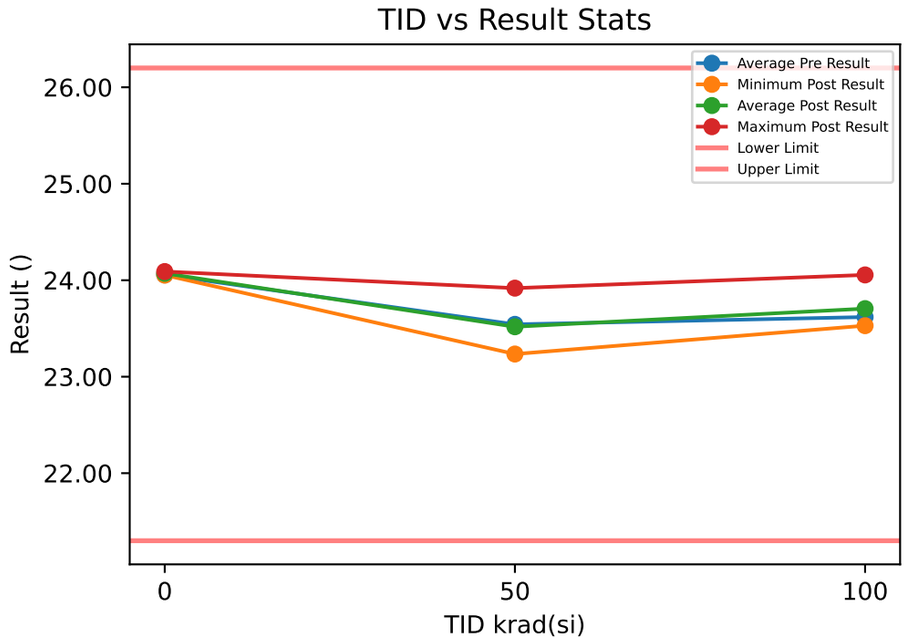
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

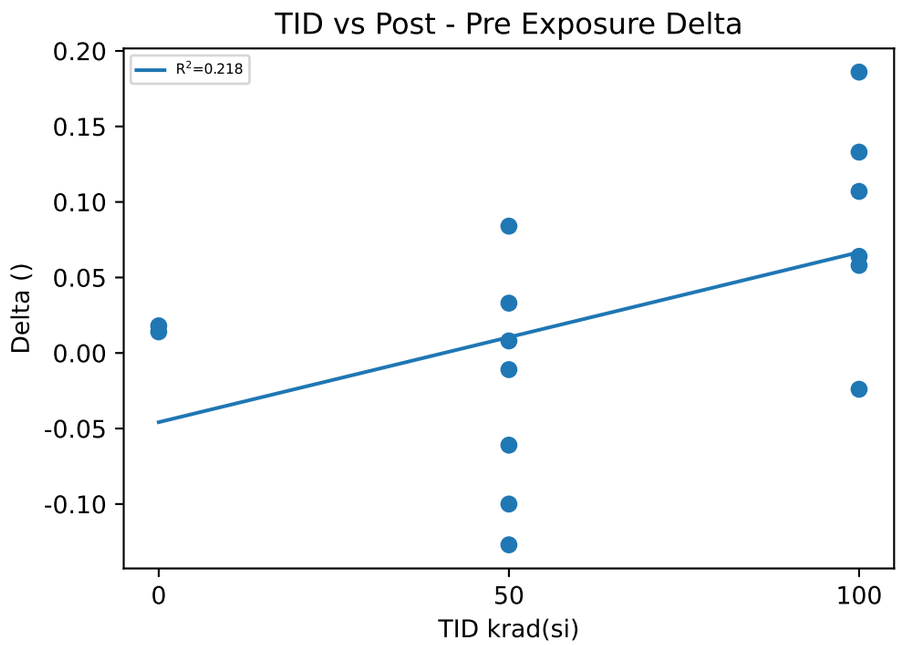
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.603	23.503	-0.1
89	50	Biased	23.818	23.916	0.098
90	50	Biased	23.587	23.511	-0.076
92	50	Biased	23.58	23.451	-0.129
93	50	Unbiased	23.346	23.228	-0.118
94	50	Unbiased	23.537	23.527	-0.01
95	50	Unbiased	23.439	23.445	0.006
96	100	Biased	23.534	23.59	0.056
97	100	Biased	23.572	23.759	0.187
98	100	Biased	23.457	23.532	0.075
99	100	Unbiased	23.939	24.046	0.107
100	100	Unbiased	23.558	23.537	-0.021
101	100	Unbiased	23.588	23.737	0.149
102	0	Correlation	24.01	24.047	0.037
103	0	Correlation	24.026	24.08	0.054

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.01	24.018	24.026	0.011314	24.047	24.063	24.08	0.023335	0.037	0.0455	0.054	0.012021
50	23.346	23.559	23.818	0.14748	23.228	23.512	23.916	0.2051	-0.129	-0.047	0.098	0.082278
100	23.457	23.608	23.939	0.16854	23.532	23.7	24.046	0.19568	-0.021	0.092167	0.187	0.073284

Device Test: 5.55 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB4_SD/RESETB4/1.6/14/1.18M/0/0/@DLY_TMR_1MOHM)





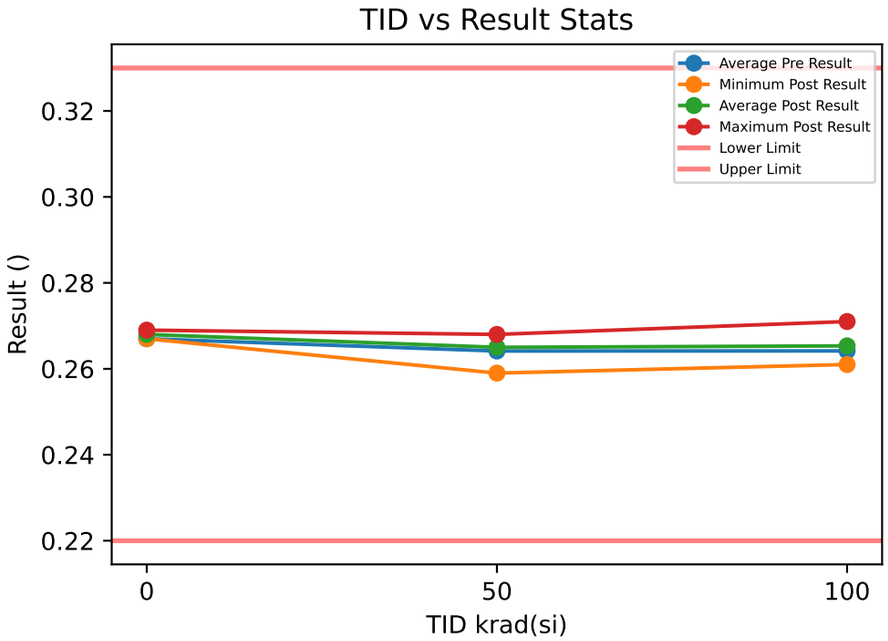
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

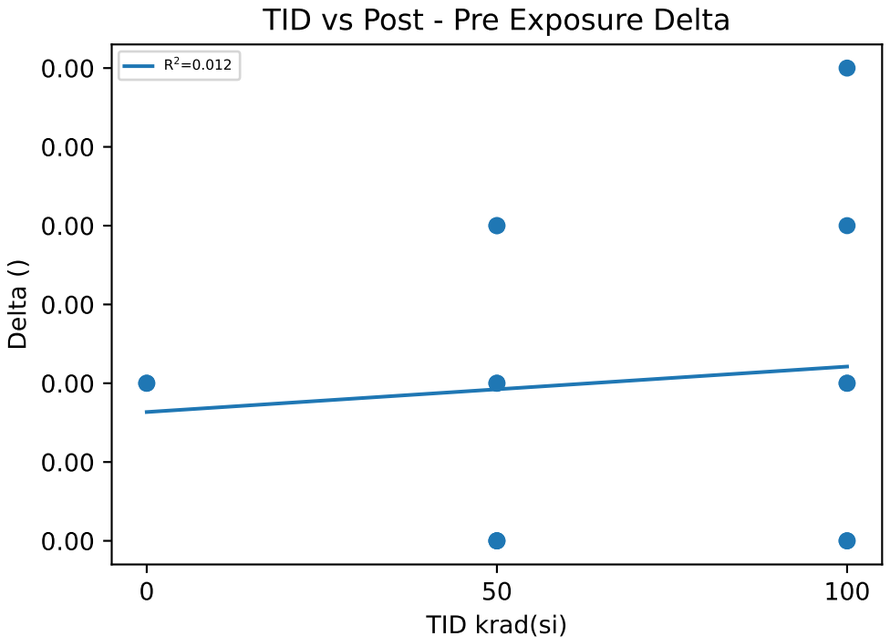
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.61	23.51	-0.1
89	50	Biased	23.834	23.918	0.084
90	50	Biased	23.577	23.516	-0.061
92	50	Biased	23.585	23.458	-0.127
93	50	Unbiased	23.202	23.235	0.033
94	50	Unbiased	23.543	23.532	-0.011
95	50	Unbiased	23.447	23.455	0.008
96	100	Biased	23.541	23.599	0.058
97	100	Biased	23.579	23.765	0.186
98	100	Biased	23.465	23.529	0.064
99	100	Unbiased	23.948	24.055	0.107
100	100	Unbiased	23.568	23.544	-0.024
101	100	Unbiased	23.609	23.742	0.133
102	0	Correlation	24.035	24.053	0.018
103	0	Correlation	24.076	24.09	0.014

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.035	24.056	24.076	0.028991	24.053	24.072	24.09	0.026163	0.014	0.016	0.018	0.0028284
50	23.202	23.543	23.834	0.19043	23.235	23.518	23.918	0.20327	-0.127	-0.024857	0.084	0.075116
100	23.465	23.618	23.948	0.16872	23.529	23.706	24.055	0.19779	-0.024	0.087333	0.186	0.072121

Device Test: 5.56 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB1_SU/RESETB1/7/3/10.5K/0/0/@DLY_TMR_10KOHM)





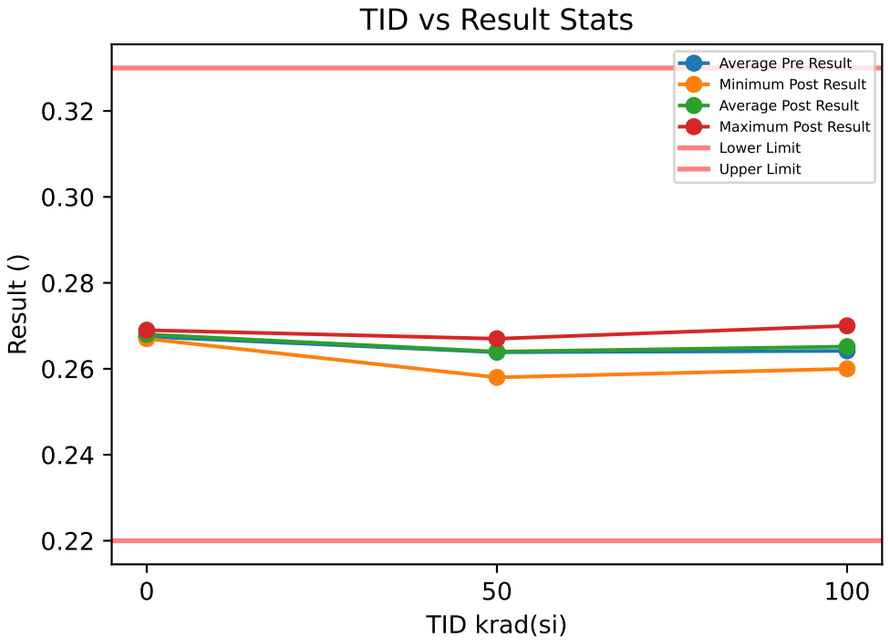
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

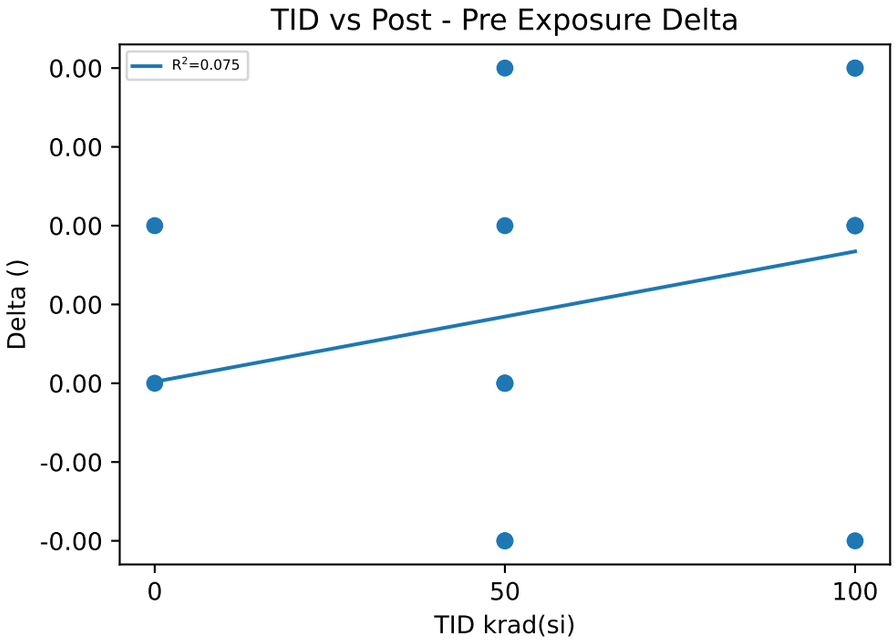
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.267	0.267	0
89	50	Biased	0.266	0.266	0
90	50	Biased	0.258	0.259	0.001
92	50	Biased	0.266	0.268	0.002
93	50	Unbiased	0.258	0.26	0.002
94	50	Unbiased	0.267	0.268	0.001
95	50	Unbiased	0.267	0.267	0
96	100	Biased	0.262	0.262	0
97	100	Biased	0.268	0.271	0.003
98	100	Biased	0.266	0.267	0.001
99	100	Unbiased	0.26	0.262	0.002
100	100	Unbiased	0.261	0.261	0
101	100	Unbiased	0.268	0.269	0.001
102	0	Correlation	0.268	0.269	0.001
103	0	Correlation	0.266	0.267	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.266	0.267	0.268	0.0014142	0.267	0.268	0.269	0.0014142	0.001	0.001	0.001	0
50	0.258	0.26414	0.267	0.0042201	0.259	0.265	0.268	0.0038297	0	0.00085714	0.002	0.00089974
100	0.26	0.26417	0.268	0.0036009	0.261	0.26533	0.271	0.0042269	0	0.0011667	0.003	0.001169

Device Test: 5.57 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB3_SU/RESETB3/7/3/10.5K/0/0/@DLY_TMR_10KOHM)





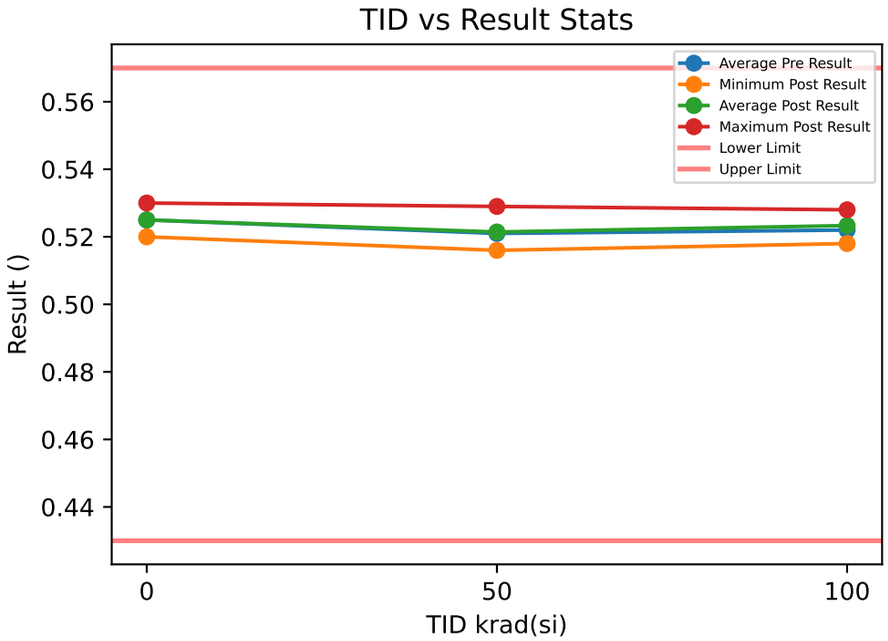
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

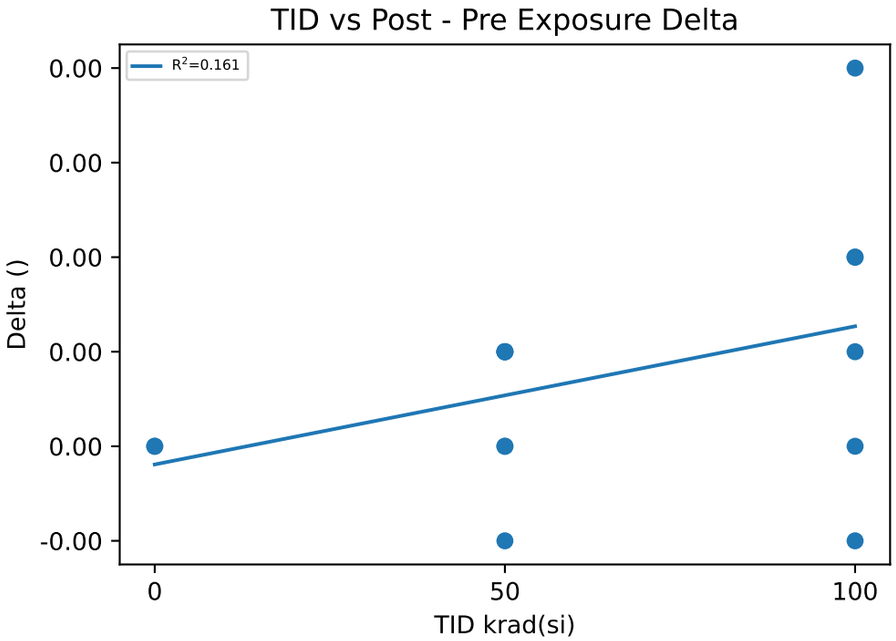
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.265	0.266	0.001
89	50	Biased	0.265	0.265	0
90	50	Biased	0.258	0.258	0
92	50	Biased	0.267	0.266	-0.001
93	50	Unbiased	0.259	0.259	0
94	50	Unbiased	0.268	0.267	-0.001
95	50	Unbiased	0.265	0.267	0.002
96	100	Biased	0.261	0.262	0.001
97	100	Biased	0.268	0.27	0.002
98	100	Biased	0.266	0.267	0.001
99	100	Unbiased	0.261	0.263	0.002
100	100	Unbiased	0.261	0.26	-0.001
101	100	Unbiased	0.268	0.269	0.001
102	0	Correlation	0.268	0.269	0.001
103	0	Correlation	0.267	0.267	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.267	0.2675	0.268	0.00070711	0.267	0.268	0.269	0.0014142	0	0.0005	0.001	0.00070711
50	0.258	0.26386	0.268	0.0038483	0.258	0.264	0.267	0.0038297	-0.001	0.00014286	0.002	0.001069
100	0.261	0.26417	0.268	0.0035449	0.26	0.26517	0.27	0.0040702	-0.001	0.001	0.002	0.0010954

Device Test: 5.58 WD_TMR_10KOHM(twd_Res10p5K_WDOB_SU/WDOB/7/3/10.5K/0/0/@WD_TMR_10KOHM)





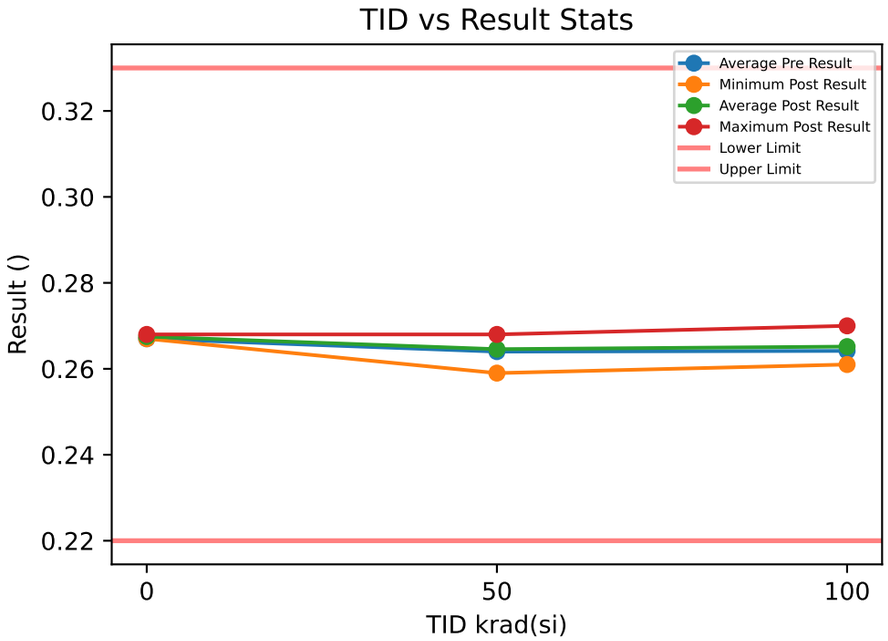
Test Results (Lower Limit = 0.43, Upper Limit = 0.57 ())

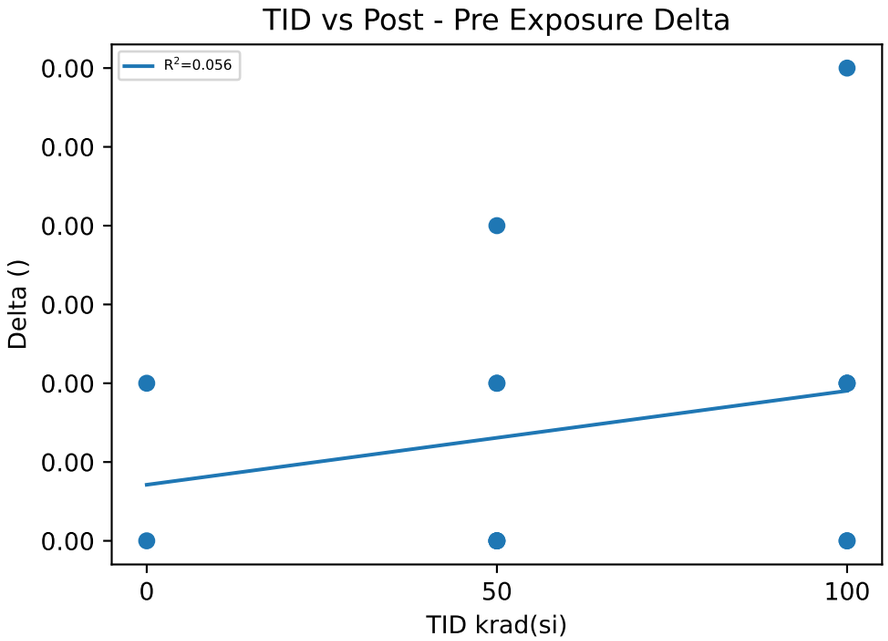
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.522	0.521	-0.001
89	50	Biased	0.515	0.516	0.001
90	50	Biased	0.517	0.518	0.001
92	50	Biased	0.524	0.525	0.001
93	50	Unbiased	0.517	0.518	0.001
94	50	Unbiased	0.529	0.529	0
95	50	Unbiased	0.523	0.523	0
96	100	Biased	0.521	0.52	-0.001
97	100	Biased	0.525	0.526	0.001
98	100	Biased	0.518	0.518	0
99	100	Unbiased	0.524	0.528	0.004
100	100	Unbiased	0.52	0.522	0.002
101	100	Unbiased	0.524	0.526	0.002
102	0	Correlation	0.53	0.53	0
103	0	Correlation	0.52	0.52	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.52	0.525	0.53	0.0070711	0.52	0.525	0.53	0.0070711	0	0	0	0
50	0.515	0.521	0.529	0.0049329	0.516	0.52143	0.529	0.0045774	-0.001	0.00042857	0.001	0.0007868
100	0.518	0.522	0.525	0.0027568	0.518	0.52333	0.528	0.0039328	-0.001	0.0013333	0.004	0.0017512

Device Test: 5.59 DLY_TMR_10KOHM(tdly_Res10p5K_PWRGD_SU/PWRGD/7/3/10.5K/0/0/@DLY_TMR_10KOHM)





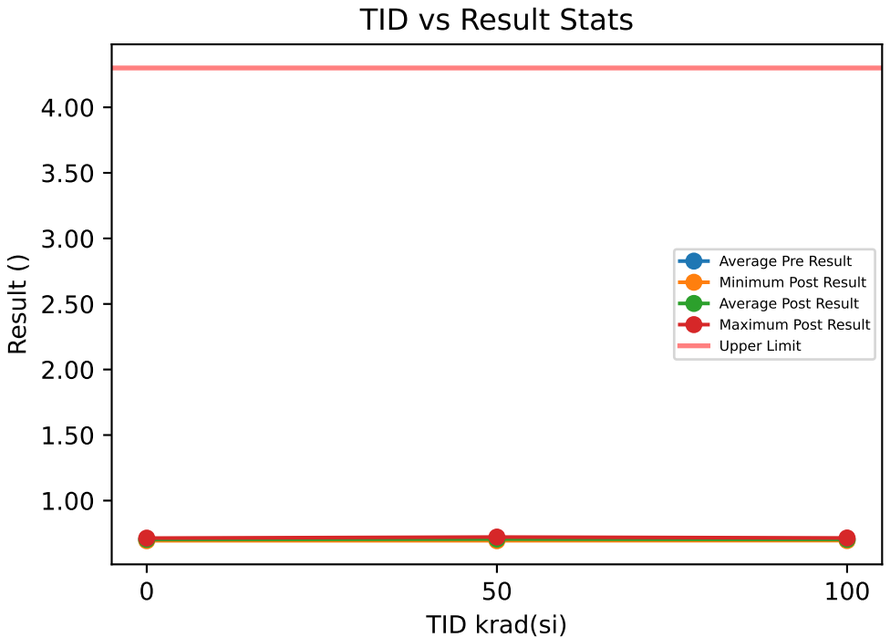
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

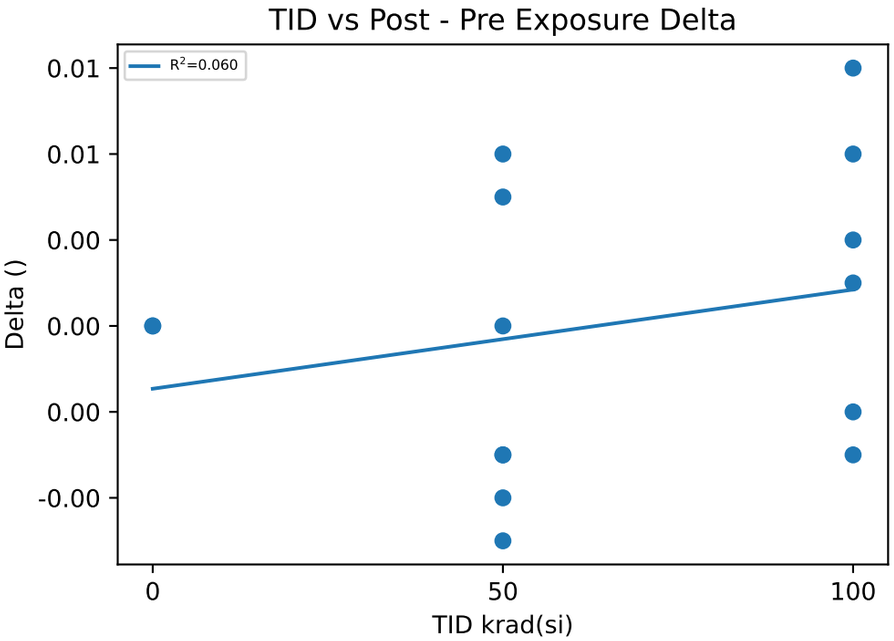
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.266	0.267	0.001
89	50	Biased	0.266	0.266	0
90	50	Biased	0.258	0.259	0.001
92	50	Biased	0.266	0.266	0
93	50	Unbiased	0.258	0.26	0.002
94	50	Unbiased	0.268	0.268	0
95	50	Unbiased	0.266	0.266	0
96	100	Biased	0.261	0.261	0
97	100	Biased	0.269	0.27	0.001
98	100	Biased	0.267	0.268	0.001
99	100	Unbiased	0.261	0.262	0.001
100	100	Unbiased	0.259	0.262	0.003
101	100	Unbiased	0.268	0.268	0
102	0	Correlation	0.268	0.268	0
103	0	Correlation	0.266	0.267	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.266	0.267	0.268	0.0014142	0.267	0.2675	0.268	0.00070711	0	0.0005	0.001	0.00070711
50	0.258	0.264	0.268	0.0041633	0.259	0.26457	0.268	0.0035523	0	0.00057143	0.002	0.0007868
100	0.259	0.26417	0.269	0.0043089	0.261	0.26517	0.27	0.00392	0	0.001	0.003	0.0010954

Device Test: 5.6 PROPD_RESET(tpd_RESETB3_SU/RESETB3/1.6/14/0/0/0/@PROPD_RESET)





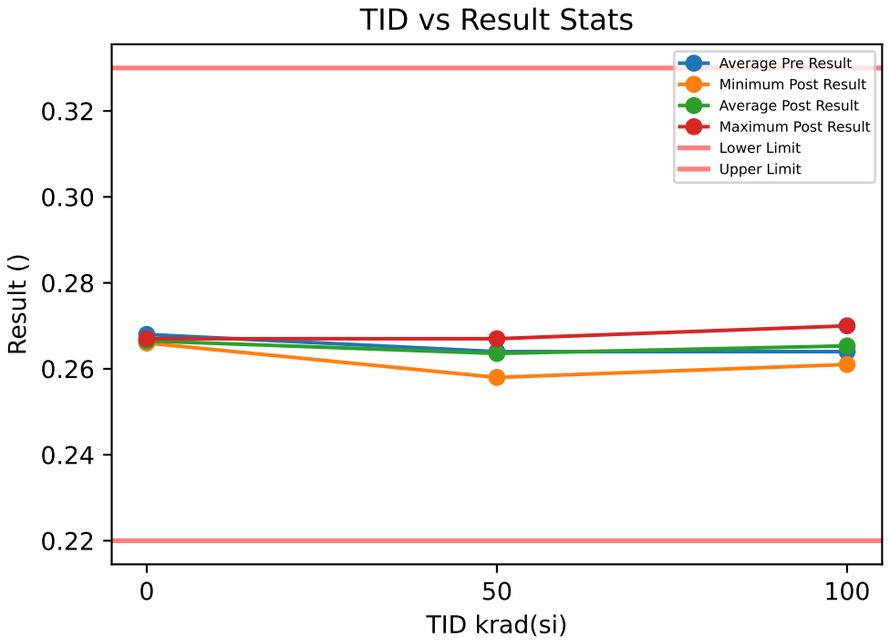
Test Results (Upper Limit = 4.3 ())

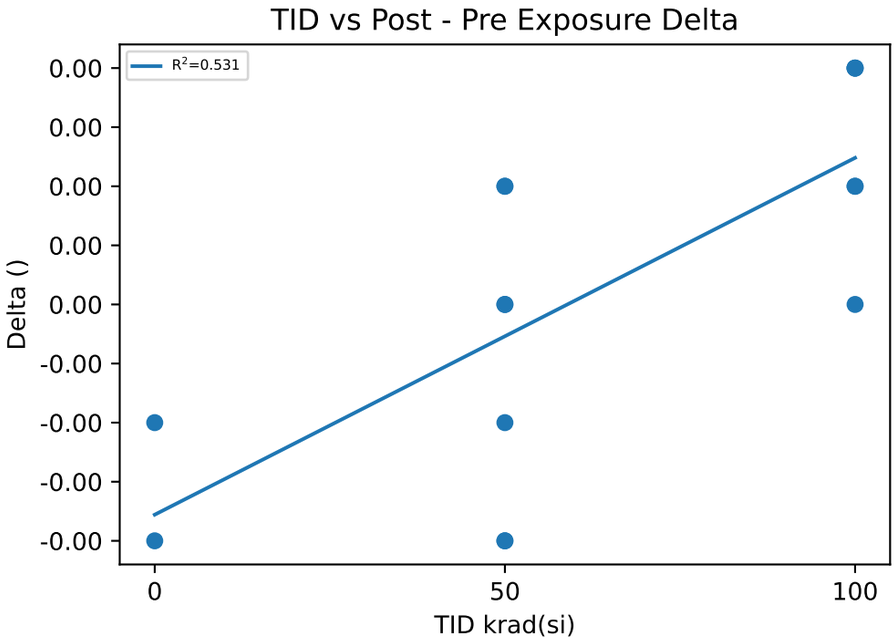
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.698	0.7	0.002
89	50	Biased	0.708	0.707	-0.001
90	50	Biased	0.696	0.694	-0.002
92	50	Biased	0.694	0.699	0.005
93	50	Unbiased	0.716	0.722	0.006
94	50	Unbiased	0.71	0.707	-0.003
95	50	Unbiased	0.718	0.717	-0.001
96	100	Biased	0.689	0.695	0.006
97	100	Biased	0.705	0.708	0.003
98	100	Biased	0.707	0.706	-0.001
99	100	Unbiased	0.704	0.704	0
100	100	Unbiased	0.711	0.715	0.004
101	100	Unbiased	0.689	0.697	0.008
102	0	Correlation	0.712	0.714	0.002
103	0	Correlation	0.692	0.694	0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.692	0.702	0.712	0.014142	0.694	0.704	0.714	0.014142	0.002	0.002	0.002	0
50	0.694	0.70571	0.718	0.009759	0.694	0.70657	0.722	0.010048	-0.003	0.00085714	0.006	0.0035322
100	0.689	0.70083	0.711	0.0094745	0.695	0.70417	0.715	0.0073598	-0.001	0.0033333	0.008	0.0034448

Device Test: 5.60 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB2_SD/RESETB2/7/3/10.5K/0/0/@DLY_TMR_10KOHM)





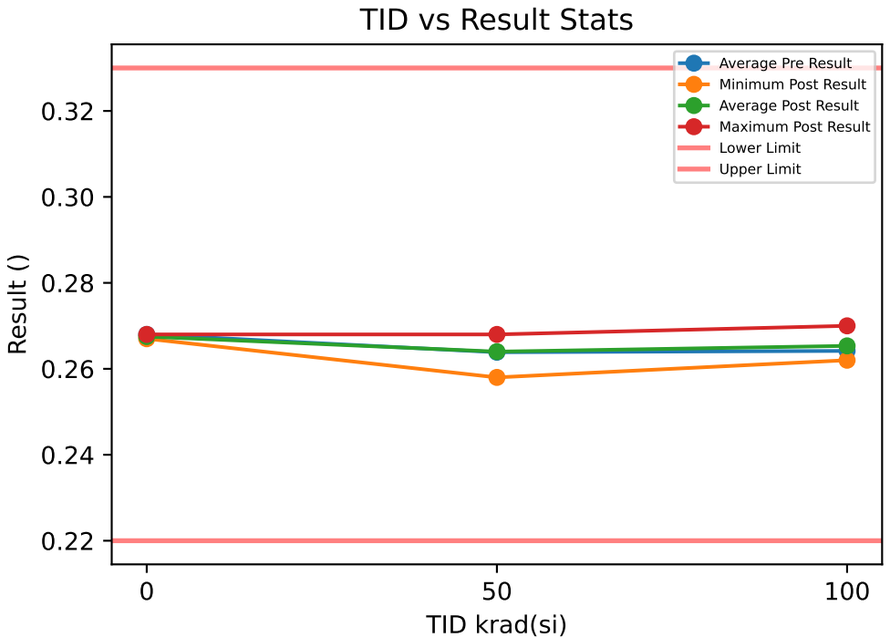
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

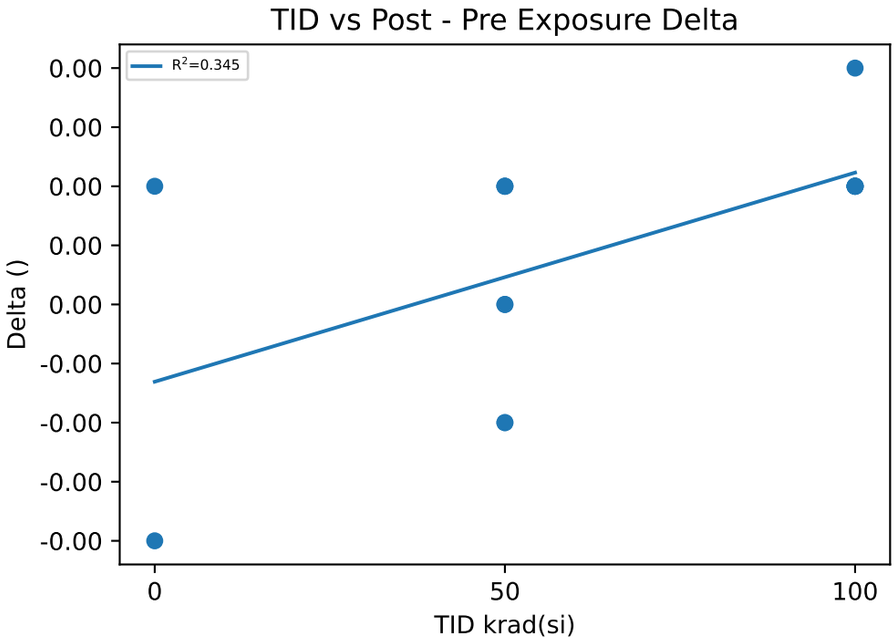
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.267	0.265	-0.002
89	50	Biased	0.266	0.264	-0.002
90	50	Biased	0.258	0.258	0
92	50	Biased	0.265	0.266	0.001
93	50	Unbiased	0.259	0.259	0
94	50	Unbiased	0.268	0.267	-0.001
95	50	Unbiased	0.265	0.266	0.001
96	100	Biased	0.261	0.261	0
97	100	Biased	0.268	0.27	0.002
98	100	Biased	0.266	0.268	0.002
99	100	Unbiased	0.262	0.263	0.001
100	100	Unbiased	0.259	0.261	0.002
101	100	Unbiased	0.268	0.269	0.001
102	0	Correlation	0.269	0.267	-0.002
103	0	Correlation	0.267	0.266	-0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.267	0.268	0.269	0.0014142	0.266	0.2665	0.267	0.00070711	-0.002	-0.0015	-0.001	0.00070711
50	0.258	0.264	0.268	0.0039158	0.258	0.26357	0.267	0.0035989	-0.002	-0.00042857	0.001	0.0012724
100	0.259	0.264	0.268	0.0038471	0.261	0.26533	0.27	0.0041312	0	0.0013333	0.002	0.0008165

Device Test: 5.61 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB4_SD/RESETB4/7/3/10.5K/0/0/@DLY_TMR_10KOHM)





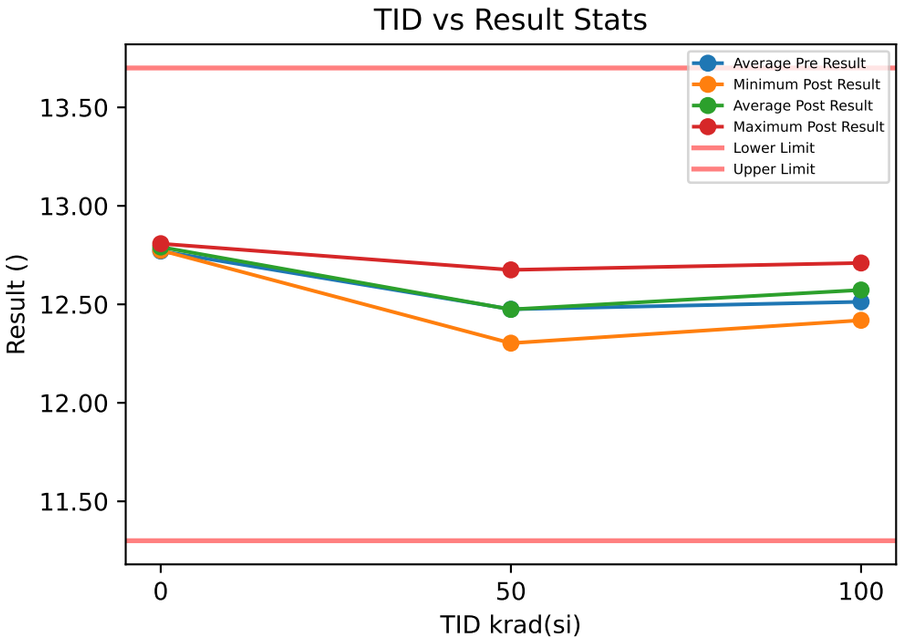
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

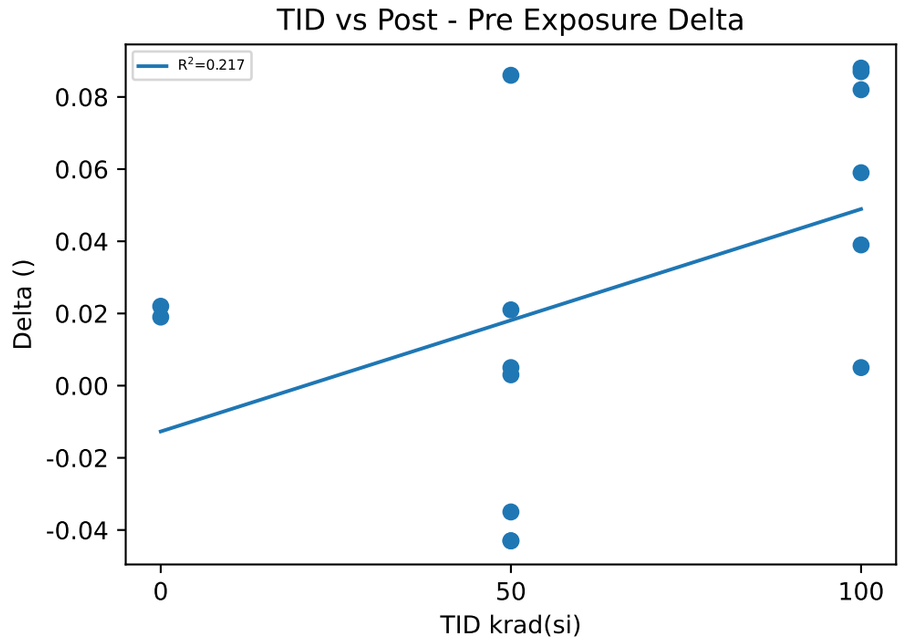
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.265	0.266	0.001
89	50	Biased	0.265	0.265	0
90	50	Biased	0.257	0.258	0.001
92	50	Biased	0.267	0.266	-0.001
93	50	Unbiased	0.258	0.259	0.001
94	50	Unbiased	0.268	0.268	0
95	50	Unbiased	0.267	0.266	-0.001
96	100	Biased	0.261	0.262	0.001
97	100	Biased	0.269	0.27	0.001
98	100	Biased	0.266	0.267	0.001
99	100	Unbiased	0.261	0.262	0.001
100	100	Unbiased	0.261	0.262	0.001
101	100	Unbiased	0.267	0.269	0.002
102	0	Correlation	0.269	0.267	-0.002
103	0	Correlation	0.267	0.268	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.267	0.268	0.269	0.0014142	0.267	0.2675	0.268	0.00070711	-0.002	-0.0005	0.001	0.0021213
50	0.257	0.26386	0.268	0.0044881	0.258	0.264	0.268	0.003873	-0.001	0.00014286	0.001	0.00089974
100	0.261	0.26417	0.269	0.0036009	0.262	0.26533	0.27	0.0037771	0.001	0.0011667	0.002	0.00040825

Device Test: 5.62 DLY_TMR_500KOHM(tdly_Res619K_RESETB1_SU/RESETB1/7/3/619K/0/0/@DLY_TMR_500KOHM)





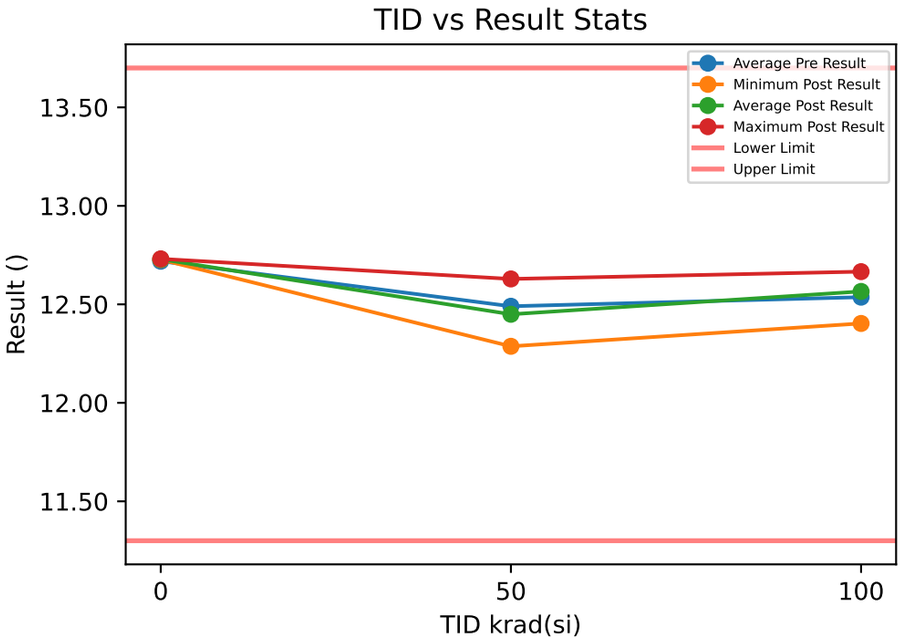
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

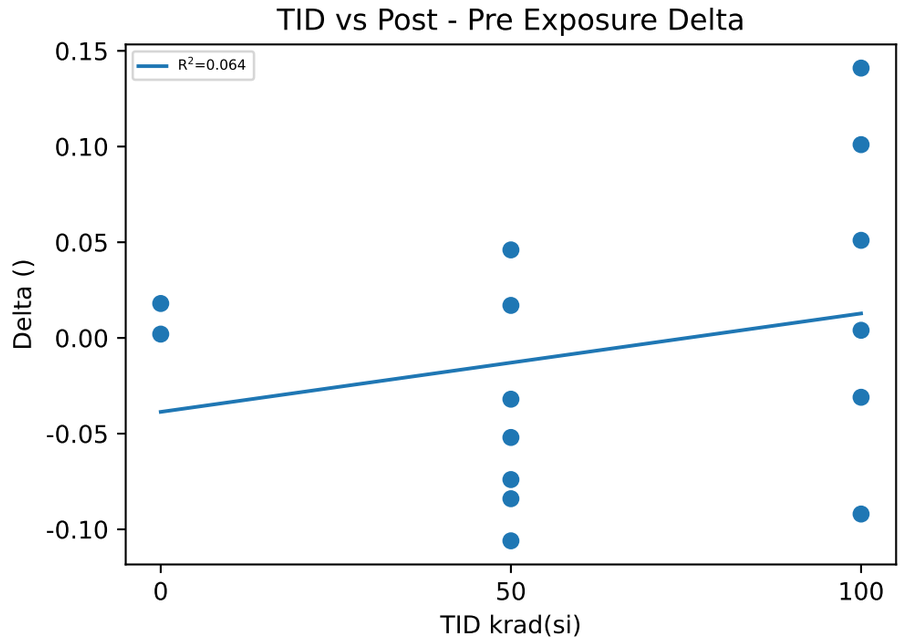
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.555	12.512	-0.043
89	50	Biased	12.589	12.675	0.086
90	50	Biased	12.391	12.394	0.003
92	50	Biased	12.487	12.452	-0.035
93	50	Unbiased	12.346	12.303	-0.043
94	50	Unbiased	12.513	12.518	0.005
95	50	Unbiased	12.445	12.466	0.021
96	100	Biased	12.418	12.457	0.039
97	100	Biased	12.562	12.644	0.082
98	100	Biased	12.502	12.561	0.059
99	100	Unbiased	12.622	12.71	0.088
100	100	Unbiased	12.414	12.419	0.005
101	100	Unbiased	12.559	12.646	0.087
102	0	Correlation	12.755	12.774	0.019
103	0	Correlation	12.786	12.808	0.022

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.755	12.771	12.786	0.02192	12.774	12.791	12.808	0.024042	0.019	0.0205	0.022	0.0021213
50	12.346	12.475	12.589	0.08716	12.303	12.474	12.675	0.11545	-0.043	-0.00085714	0.086	0.046168
100	12.414	12.513	12.622	0.084077	12.419	12.573	12.71	0.11529	0.005	0.06	0.088	0.033058

Device Test: 5.63 DLY_TMR_500KOHM(tdly_Res619K_RESETB3_SU/RESETB3/7/3/619K/0/0/@DLY_TMR_500KOHM)





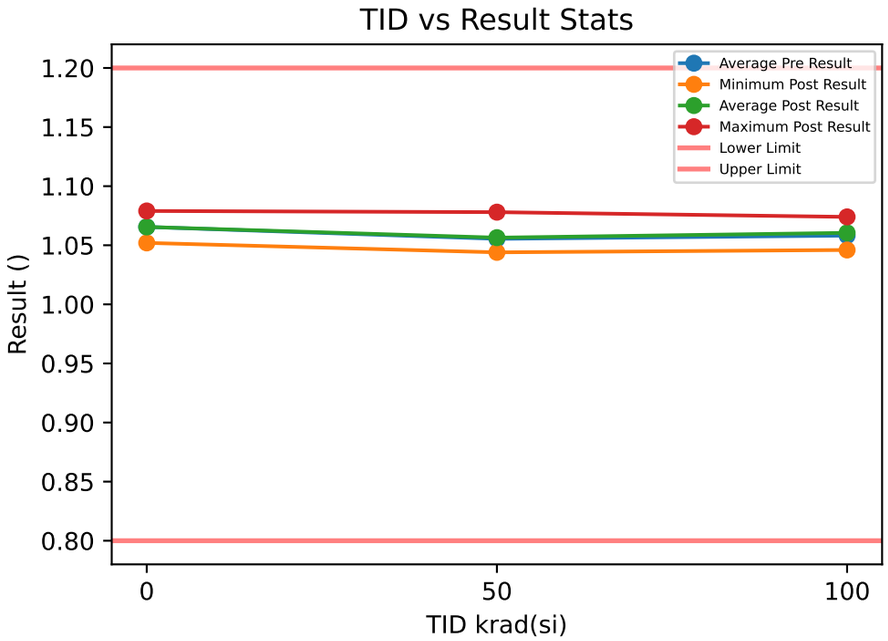
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

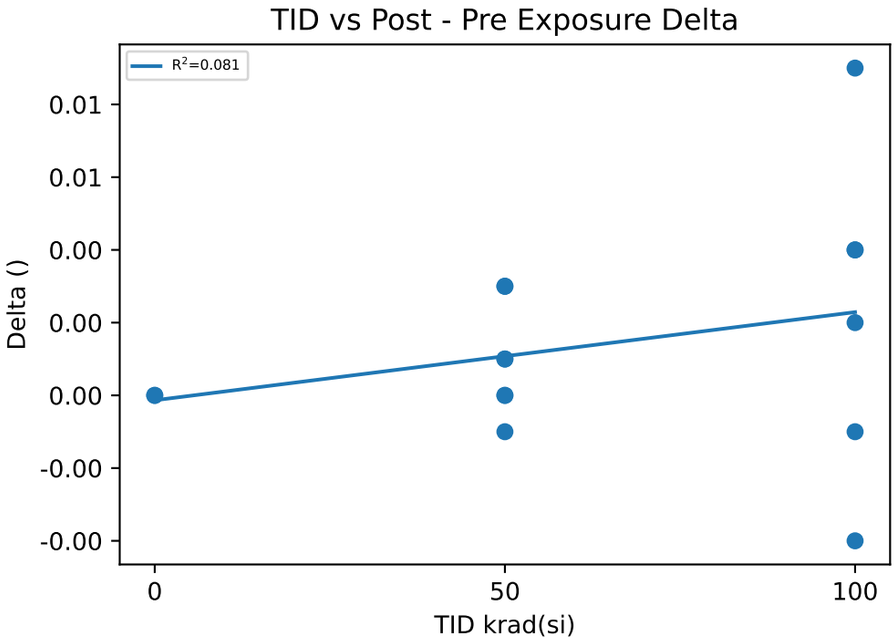
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.52	12.488	-0.032
89	50	Biased	12.583	12.629	0.046
90	50	Biased	12.476	12.37	-0.106
92	50	Biased	12.484	12.432	-0.052
93	50	Unbiased	12.361	12.287	-0.074
94	50	Unbiased	12.578	12.494	-0.084
95	50	Unbiased	12.43	12.447	0.017
96	100	Biased	12.5	12.504	0.004
97	100	Biased	12.526	12.627	0.101
98	100	Biased	12.561	12.53	-0.031
99	100	Unbiased	12.612	12.663	0.051
100	100	Unbiased	12.495	12.403	-0.092
101	100	Unbiased	12.525	12.666	0.141
102	0	Correlation	12.713	12.731	0.018
103	0	Correlation	12.725	12.727	0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.713	12.719	12.725	0.0084853	12.727	12.729	12.731	0.0028284	0.002	0.01	0.018	0.011314
50	12.361	12.49	12.583	0.079336	12.287	12.45	12.629	0.10702	-0.106	-0.040714	0.046	0.055223
100	12.495	12.536	12.612	0.043812	12.403	12.566	12.666	0.10473	-0.092	0.029	0.141	0.086114

Device Test: 5.64 WD_TMR_500KOHM(twd_Res619K_WDOB_SU/WDOB/7/3/619K/0/0/@WD_TMR_500KOHM)





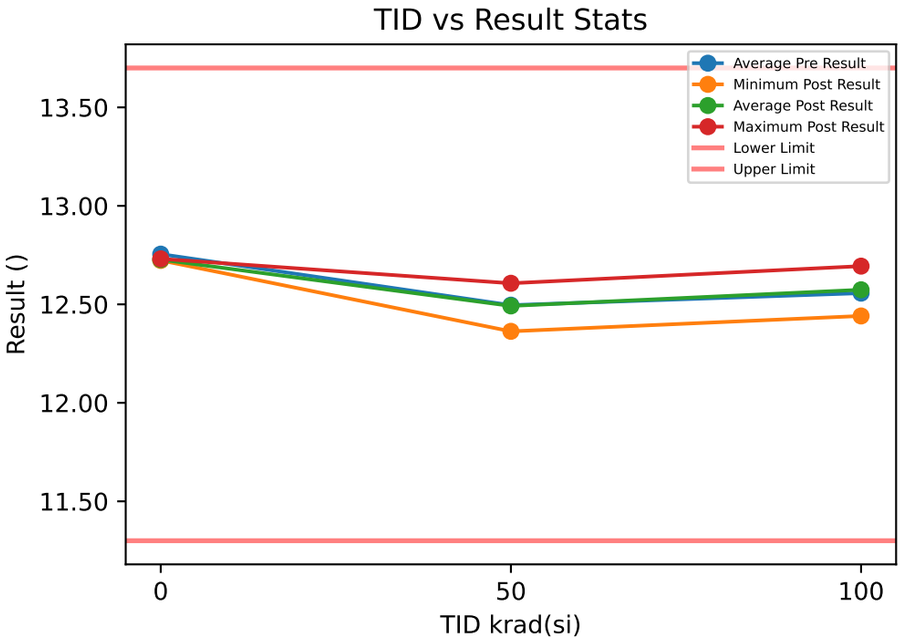
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 ())

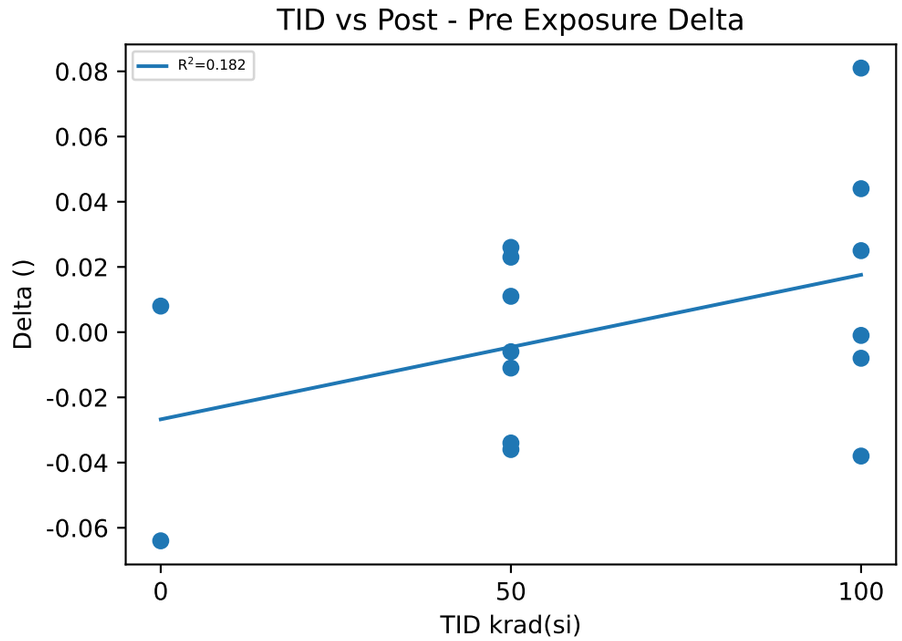
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.056	1.055	-0.001
89	50	Biased	1.041	1.044	0.003
90	50	Biased	1.044	1.045	0.001
92	50	Biased	1.065	1.066	0.001
93	50	Unbiased	1.043	1.046	0.003
94	50	Unbiased	1.078	1.078	0
95	50	Unbiased	1.061	1.061	0
96	100	Biased	1.056	1.052	-0.004
97	100	Biased	1.064	1.066	0.002
98	100	Biased	1.047	1.046	-0.001
99	100	Unbiased	1.065	1.074	0.009
100	100	Unbiased	1.052	1.056	0.004
101	100	Unbiased	1.065	1.069	0.004
102	0	Correlation	1.079	1.079	0
103	0	Correlation	1.052	1.052	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.052	1.0655	1.079	0.019092	1.052	1.0655	1.079	0.019092	0	0	0	0
50	1.041	1.0554	1.078	0.013697	1.044	1.0564	1.078	0.012739	-0.001	0.001	0.003	0.0015275
100	1.047	1.0582	1.065	0.007679	1.046	1.0605	1.074	0.01084	-0.004	0.0023333	0.009	0.0045019

Device Test: 5.65 DLY_TMR_500KOHM(tdly_Res619K_PWRGD_SU/PWRGD/7/3/619K/0/0/@DLY_TMR_500KOHM)





Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

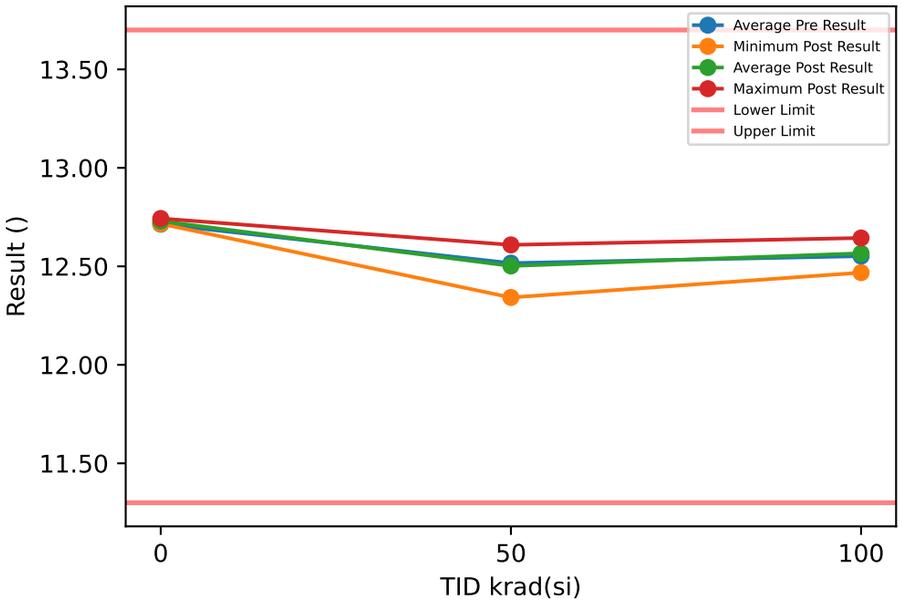
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.53	12.556	0.026
89	50	Biased	12.613	12.607	-0.006
90	50	Biased	12.447	12.436	-0.011
92	50	Biased	12.526	12.492	-0.034
93	50	Unbiased	12.352	12.363	0.011
94	50	Unbiased	12.496	12.519	0.023
95	50	Unbiased	12.507	12.471	-0.036
96	100	Biased	12.442	12.467	0.025
97	100	Biased	12.608	12.652	0.044
98	100	Biased	12.555	12.517	-0.038
99	100	Unbiased	12.695	12.694	-0.001
100	100	Unbiased	12.449	12.441	-0.008
101	100	Unbiased	12.592	12.673	0.081
102	0	Correlation	12.723	12.731	0.008
103	0	Correlation	12.787	12.723	-0.064

Test Statistics ()

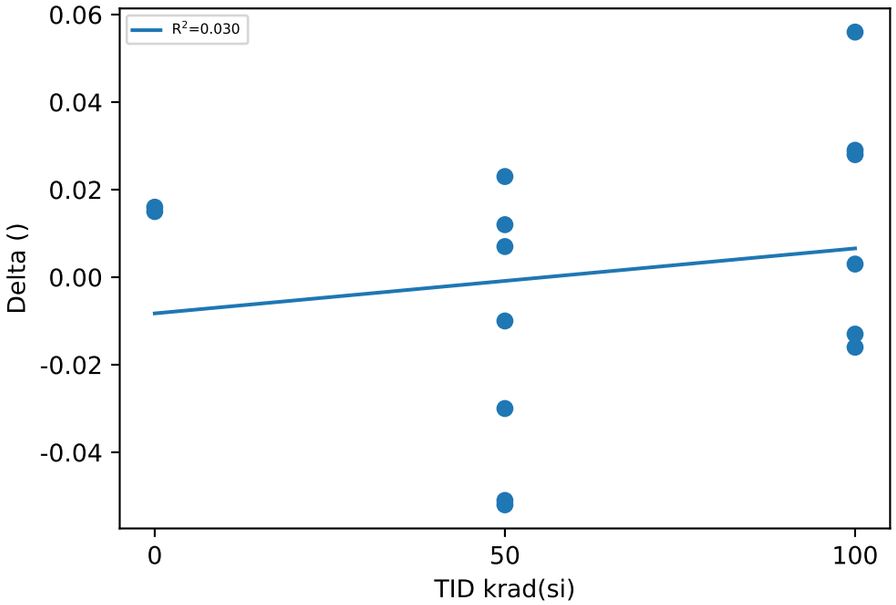
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.723	12.755	12.787	0.045255	12.723	12.727	12.731	0.0056569	-0.064	-0.028	0.008	0.050912
50	12.352	12.496	12.613	0.080626	12.363	12.492	12.607	0.079862	-0.036	-0.0038571	0.026	0.025268
100	12.442	12.557	12.695	0.097737	12.441	12.574	12.694	0.11196	-0.038	0.017167	0.081	0.042102

Device Test: 5.66 DLY_TMR_500KOHM(tdly_Res619K_RESETB2_SD/RESETB2/7/3/619K/0/0/@DLY_TMR_500KOHM)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



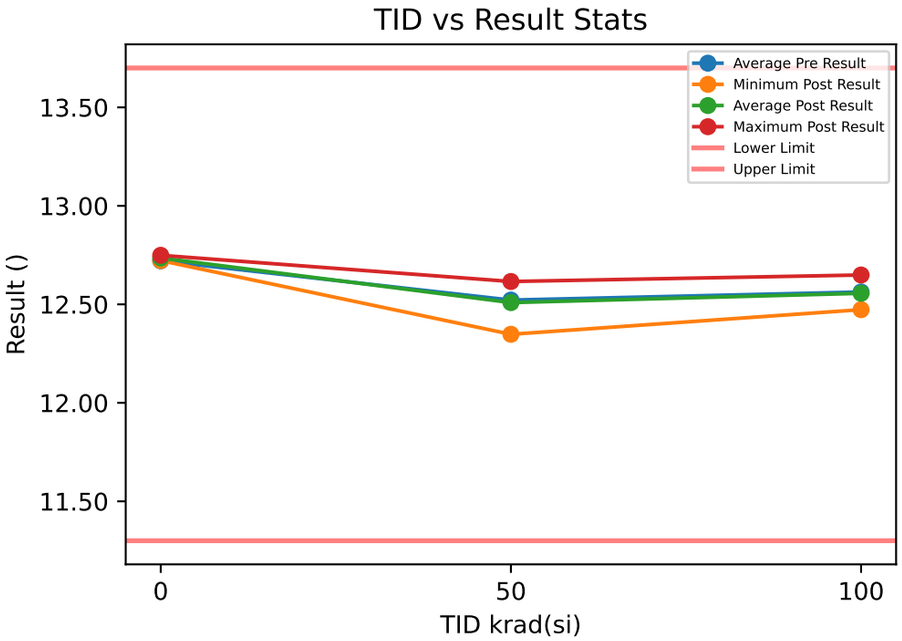
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

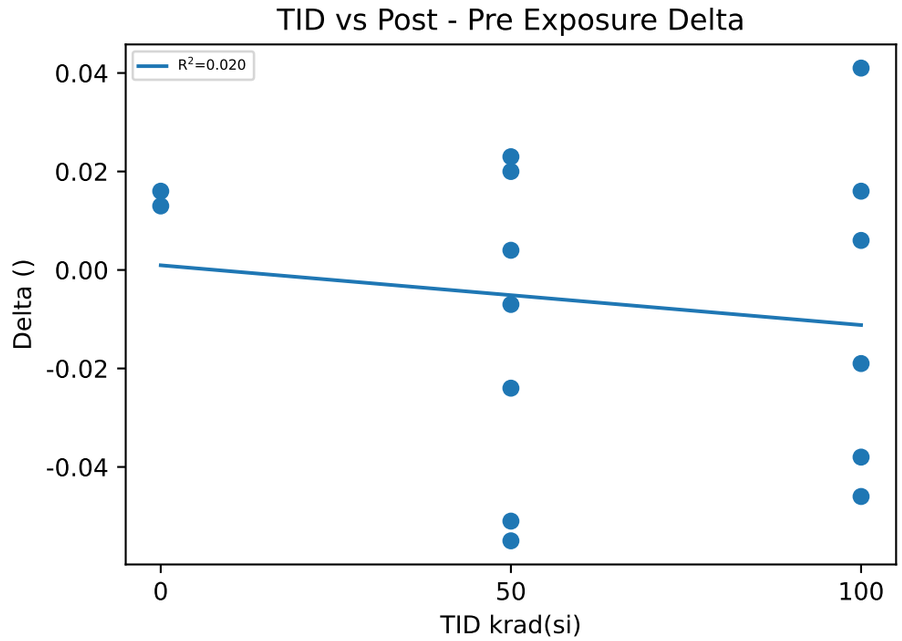
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.59	12.56	-0.03
89	50	Biased	12.66	12.609	-0.051
90	50	Biased	12.441	12.431	-0.01
92	50	Biased	12.551	12.499	-0.052
93	50	Unbiased	12.319	12.342	0.023
94	50	Unbiased	12.559	12.566	0.007
95	50	Unbiased	12.495	12.507	0.012
96	100	Biased	12.467	12.495	0.028
97	100	Biased	12.575	12.604	0.029
98	100	Biased	12.55	12.606	0.056
99	100	Unbiased	12.657	12.644	-0.013
100	100	Unbiased	12.465	12.468	0.003
101	100	Unbiased	12.596	12.58	-0.016
102	0	Correlation	12.7	12.716	0.016
103	0	Correlation	12.728	12.743	0.015

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.7	12.714	12.728	0.019799	12.716	12.729	12.743	0.019092	0.015	0.0155	0.016	0.00070711
50	12.319	12.516	12.66	0.11118	12.342	12.502	12.609	0.090907	-0.052	-0.014429	0.023	0.030468
100	12.465	12.552	12.657	0.075216	12.468	12.566	12.644	0.069237	-0.016	0.0145	0.056	0.028048

Device Test: 5.67 DLY_TMR_500KOHM(tdly_Res619K_RESETB4_SD/RESETB4/7/3/619K/0/0/@DLY_TMR_500KOHM)





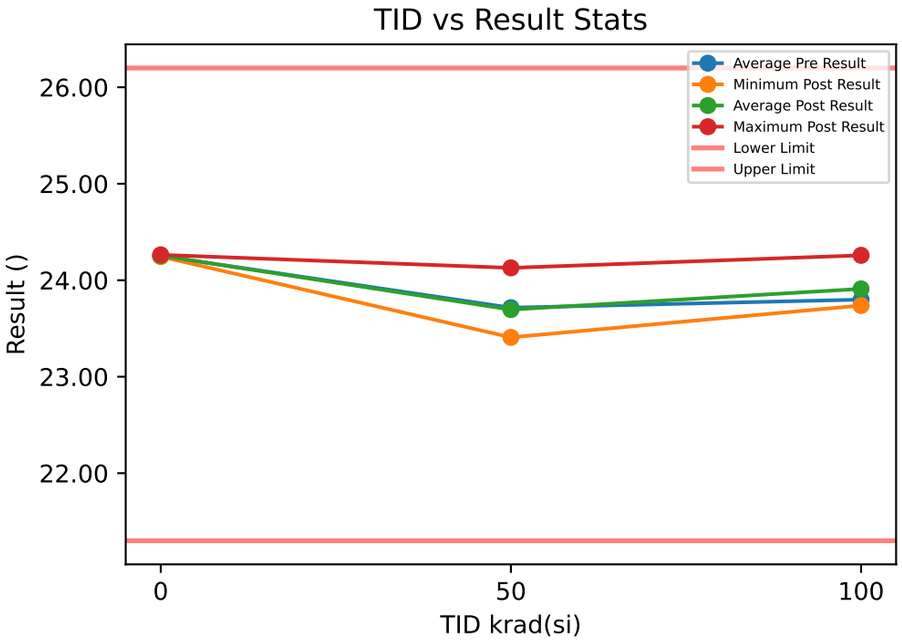
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

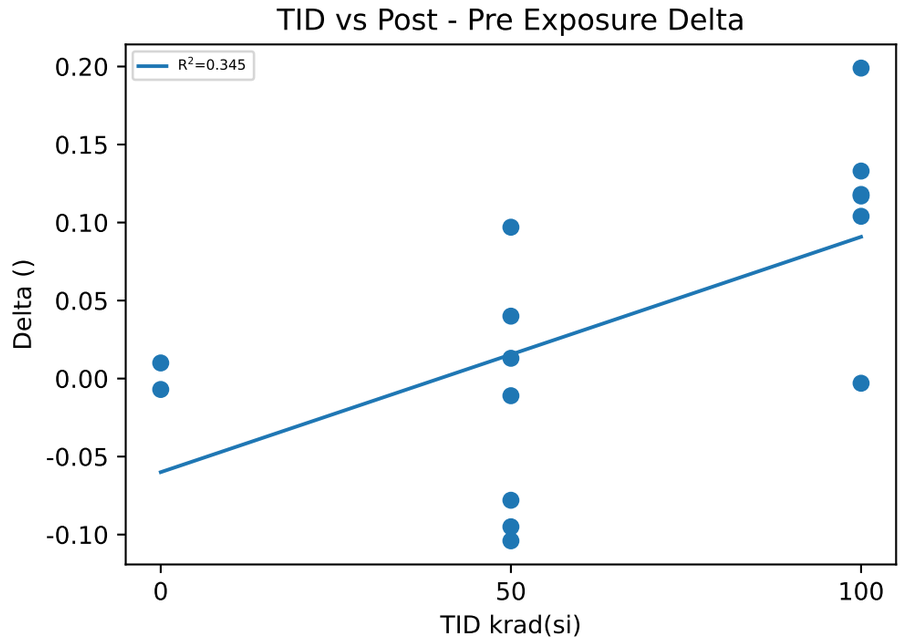
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.59	12.566	-0.024
89	50	Biased	12.667	12.616	-0.051
90	50	Biased	12.445	12.438	-0.007
92	50	Biased	12.558	12.503	-0.055
93	50	Unbiased	12.325	12.348	0.023
94	50	Unbiased	12.567	12.571	0.004
95	50	Unbiased	12.5	12.52	0.02
96	100	Biased	12.459	12.5	0.041
97	100	Biased	12.605	12.611	0.006
98	100	Biased	12.556	12.518	-0.038
99	100	Unbiased	12.695	12.649	-0.046
100	100	Unbiased	12.457	12.473	0.016
101	100	Unbiased	12.604	12.585	-0.019
102	0	Correlation	12.706	12.722	0.016
103	0	Correlation	12.736	12.749	0.013

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.706	12.721	12.736	0.021213	12.722	12.736	12.749	0.019092	0.013	0.0145	0.016	0.0021213
50	12.325	12.522	12.667	0.1112	12.348	12.509	12.616	0.090977	-0.055	-0.012857	0.023	0.031725
100	12.457	12.563	12.695	0.092703	12.473	12.556	12.649	0.069259	-0.046	-0.0066667	0.041	0.033548

Device Test: 5.68 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB1_SU/RESETB1/7/3/1.18M/0/0/@DLY_TMR_1MOHM)





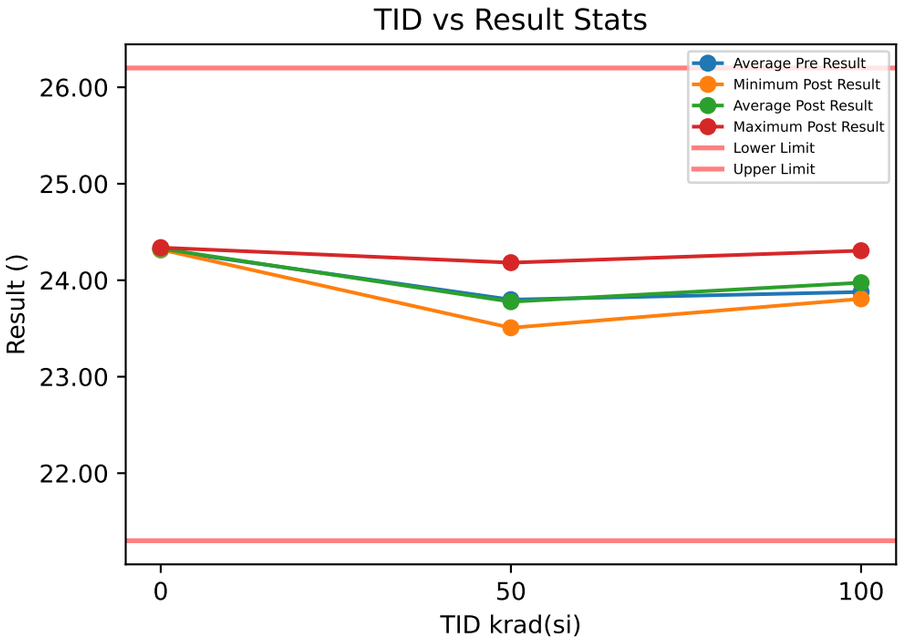
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

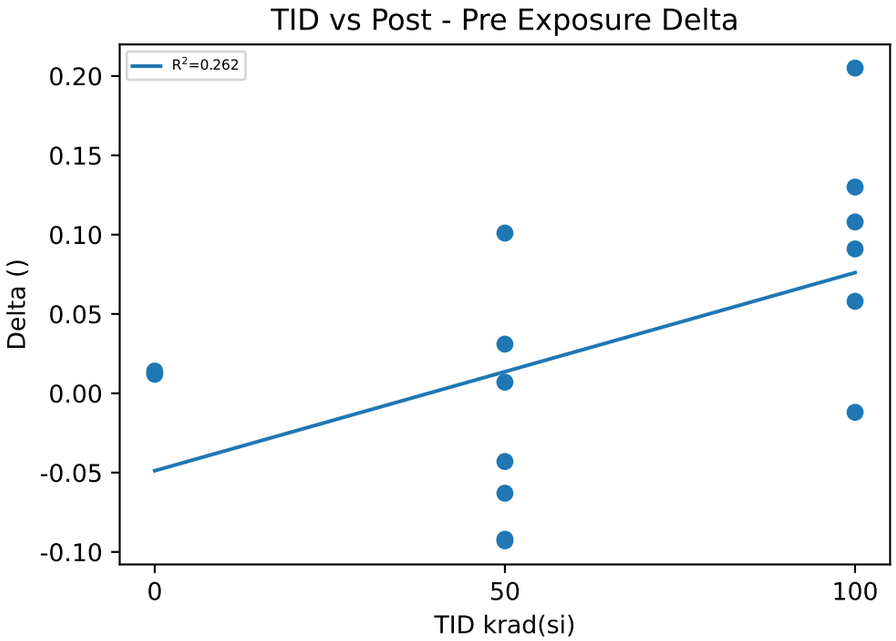
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.793	23.698	-0.095
89	50	Biased	24.031	24.128	0.097
90	50	Biased	23.76	23.682	-0.078
92	50	Biased	23.736	23.632	-0.104
93	50	Unbiased	23.368	23.408	0.04
94	50	Unbiased	23.712	23.701	-0.011
95	50	Unbiased	23.607	23.62	0.013
96	100	Biased	23.691	23.795	0.104
97	100	Biased	23.78	23.979	0.199
98	100	Biased	23.643	23.761	0.118
99	100	Unbiased	24.141	24.258	0.117
100	100	Unbiased	23.741	23.738	-0.003
101	100	Unbiased	23.799	23.932	0.133
102	0	Correlation	24.252	24.245	-0.007
103	0	Correlation	24.253	24.263	0.01

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.252	24.252	24.253	0.00070711	24.245	24.254	24.263	0.012728	-0.007	0.0015	0.01	0.012021
50	23.368	23.715	24.031	0.2002	23.408	23.696	24.128	0.21589	-0.104	-0.019714	0.097	0.075833
100	23.643	23.799	24.141	0.17702	23.738	23.91	24.258	0.19563	-0.003	0.11133	0.199	0.065356

Device Test: 5.69 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB3_SU/RESETB3/7/3/1.18M/0/0/@DLY_TMR_1MOHM)





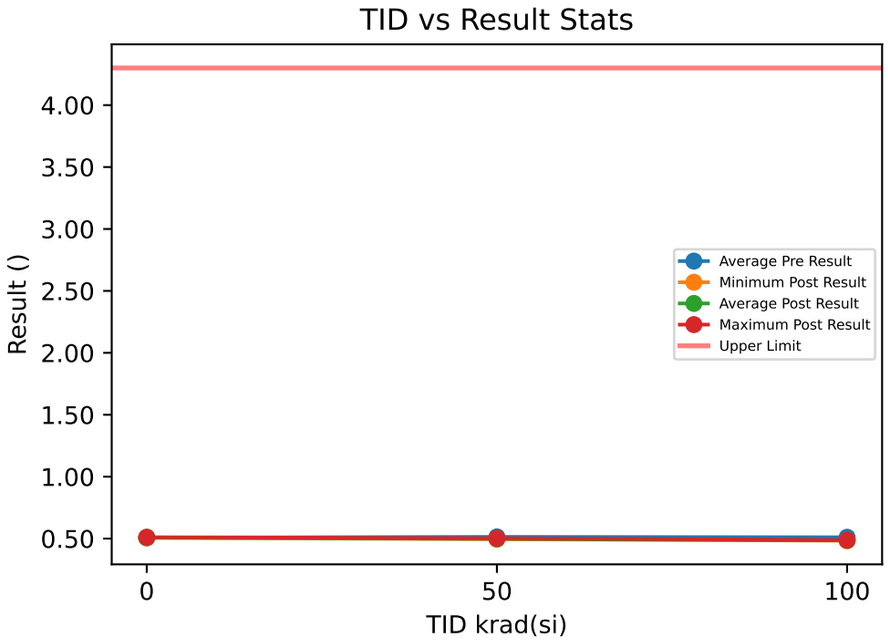
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

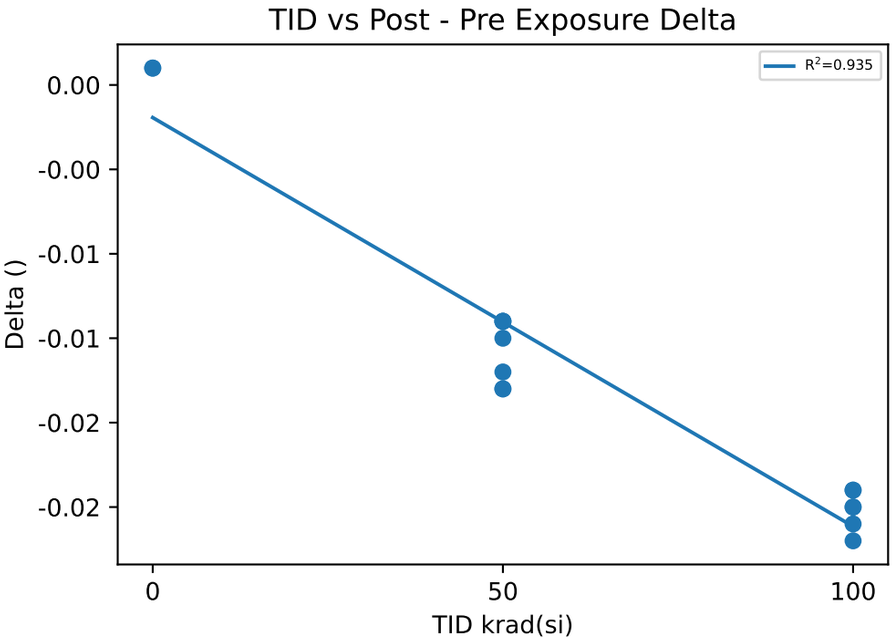
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.863	23.771	-0.092
89	50	Biased	24.081	24.182	0.101
90	50	Biased	23.839	23.776	-0.063
92	50	Biased	23.82	23.727	-0.093
93	50	Unbiased	23.476	23.507	0.031
94	50	Unbiased	23.803	23.76	-0.043
95	50	Unbiased	23.71	23.717	0.007
96	100	Biased	23.806	23.864	0.058
97	100	Biased	23.835	24.04	0.205
98	100	Biased	23.74	23.831	0.091
99	100	Unbiased	24.198	24.306	0.108
100	100	Unbiased	23.819	23.807	-0.012
101	100	Unbiased	23.869	23.999	0.13
102	0	Correlation	24.304	24.318	0.014
103	0	Correlation	24.326	24.338	0.012

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.304	24.315	24.326	0.015556	24.318	24.328	24.338	0.014142	0.012	0.013	0.014	0.0014142
50	23.476	23.799	24.081	0.18163	23.507	23.777	24.182	0.20139	-0.093	-0.021714	0.101	0.071695
100	23.74	23.878	24.198	0.1625	23.807	23.975	24.306	0.18743	-0.012	0.096667	0.205	0.072541

Device Test: 5.7 PROPD_PWRGD(tpd_PWRGD_SU/PWRGD/1.6/14/0/0/0/@PROPD_PWRGD)





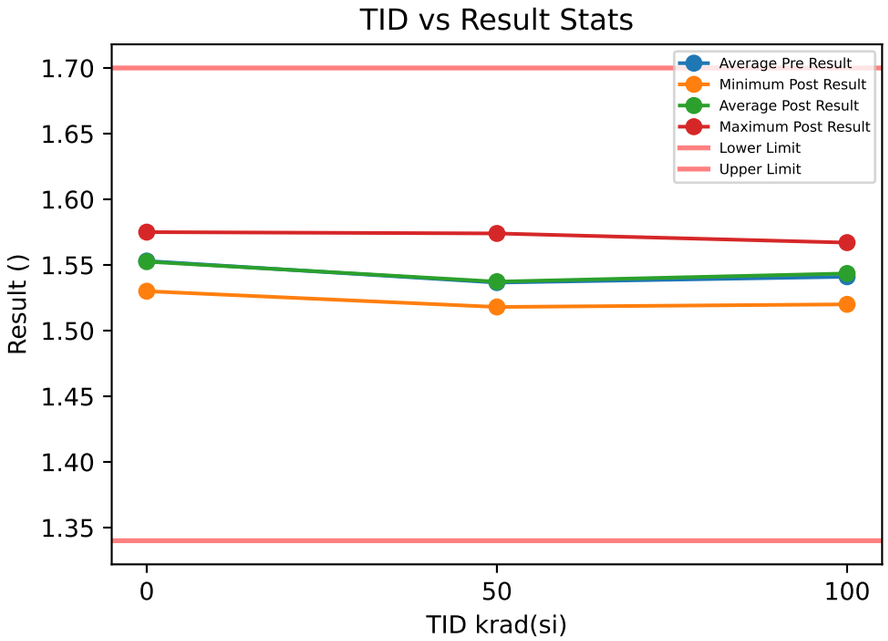
Test Results (Upper Limit = 4.3 ())

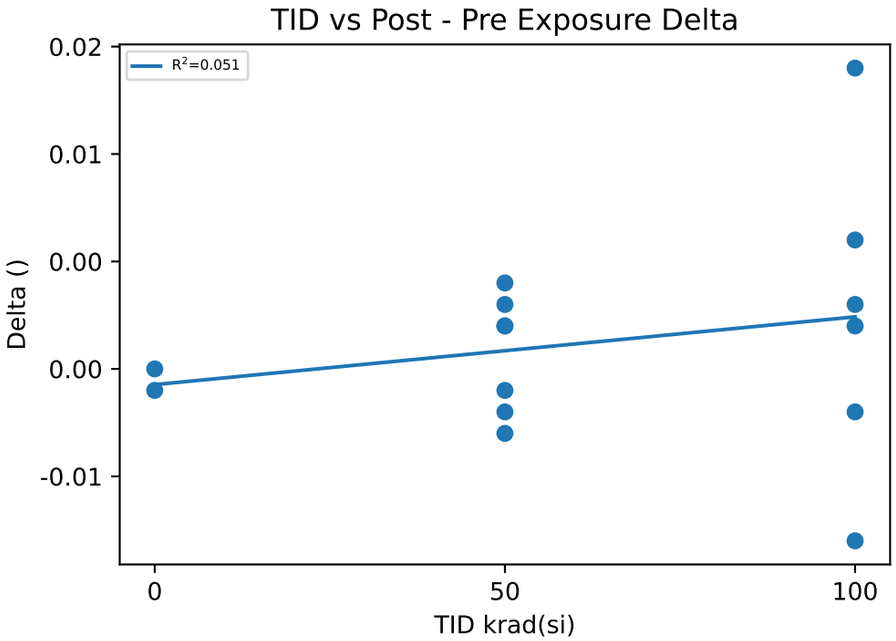
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.513	0.496	-0.017
89	50	Biased	0.514	0.5	-0.014
90	50	Biased	0.51	0.495	-0.015
92	50	Biased	0.517	0.503	-0.014
93	50	Unbiased	0.515	0.501	-0.014
94	50	Unbiased	0.513	0.495	-0.018
95	50	Unbiased	0.515	0.497	-0.018
96	100	Biased	0.511	0.486	-0.025
97	100	Biased	0.51	0.486	-0.024
98	100	Biased	0.507	0.483	-0.024
99	100	Unbiased	0.512	0.487	-0.025
100	100	Unbiased	0.515	0.488	-0.027
101	100	Unbiased	0.509	0.483	-0.026
102	0	Correlation	0.505	0.506	0.001
103	0	Correlation	0.51	0.511	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.505	0.5075	0.51	0.0035355	0.506	0.5085	0.511	0.0035355	0.001	0.001	0.001	0
50	0.51	0.51386	0.517	0.0021931	0.495	0.49814	0.503	0.0031848	-0.018	-0.015714	-0.014	0.0018898
100	0.507	0.51067	0.515	0.0027325	0.483	0.4855	0.488	0.0020736	-0.027	-0.025167	-0.024	0.001169

Device Test: 5.70 WD_TMR_1MOHM(twd_Res1p18M_WDOB_SU/WDOB/7/3/1.18M/0/0/@WD_TMR_1MOHM)





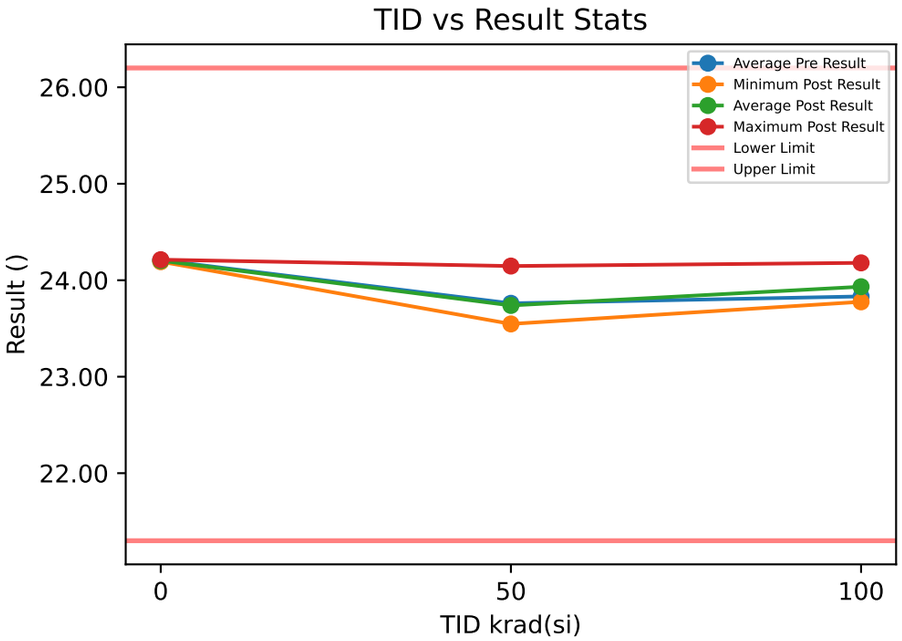
Test Results (Lower Limit = 1.34, Upper Limit = 1.7 ())

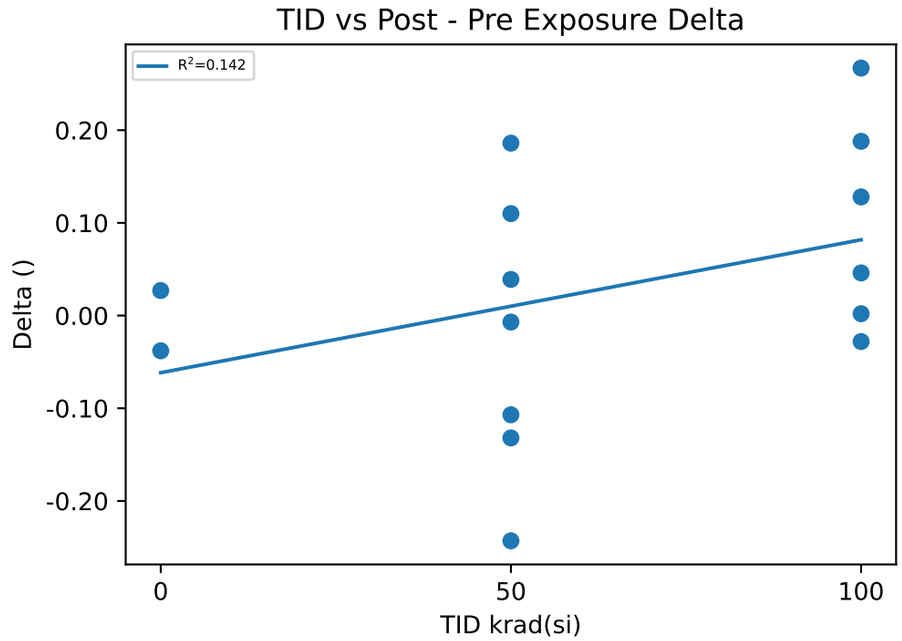
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.537	1.534	-0.003
89	50	Biased	1.514	1.518	0.004
90	50	Biased	1.516	1.518	0.002
92	50	Biased	1.552	1.554	0.002
93	50	Unbiased	1.516	1.519	0.003
94	50	Unbiased	1.575	1.574	-0.001
95	50	Unbiased	1.546	1.544	-0.002
96	100	Biased	1.538	1.53	-0.008
97	100	Biased	1.55	1.552	0.002
98	100	Biased	1.522	1.52	-0.002
99	100	Unbiased	1.553	1.567	0.014
100	100	Unbiased	1.531	1.534	0.003
101	100	Unbiased	1.552	1.558	0.006
102	0	Correlation	1.576	1.575	-0.001
103	0	Correlation	1.53	1.53	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.53	1.553	1.576	0.032527	1.53	1.5525	1.575	0.03182	-0.001	-0.0005	0	0.00070711
50	1.514	1.5366	1.575	0.022948	1.518	1.5373	1.574	0.021453	-0.003	0.00071429	0.004	0.0026904
100	1.522	1.541	1.553	0.012775	1.52	1.5435	1.567	0.018218	-0.008	0.0025	0.014	0.0074229

Device Test: 5.71 DLY_TMR_1MOHM(tdly_Res1p18M_PWRGD_SU/PWRGD/7/3/1.18M/0/0/@DLY_TMR_1MOHM)





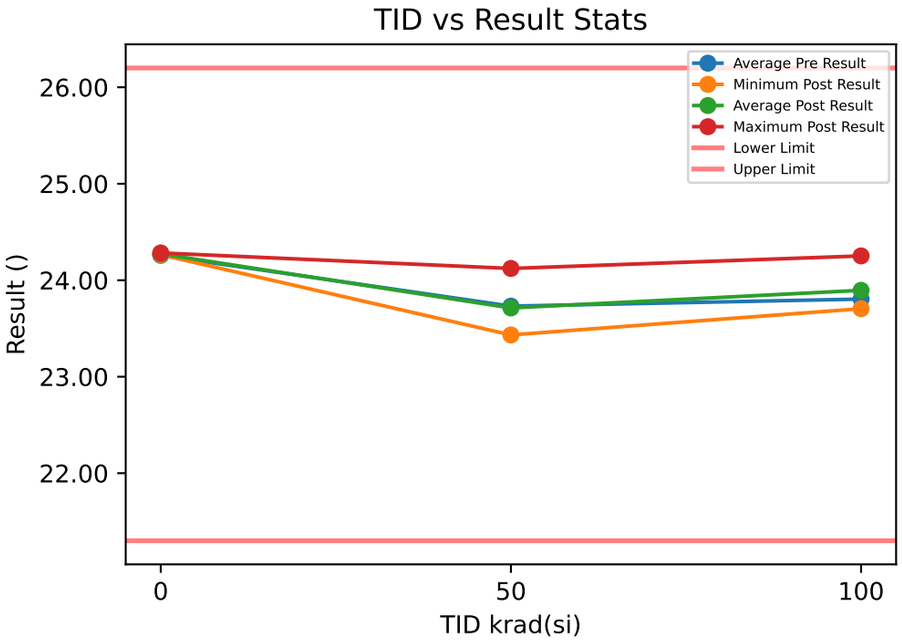
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

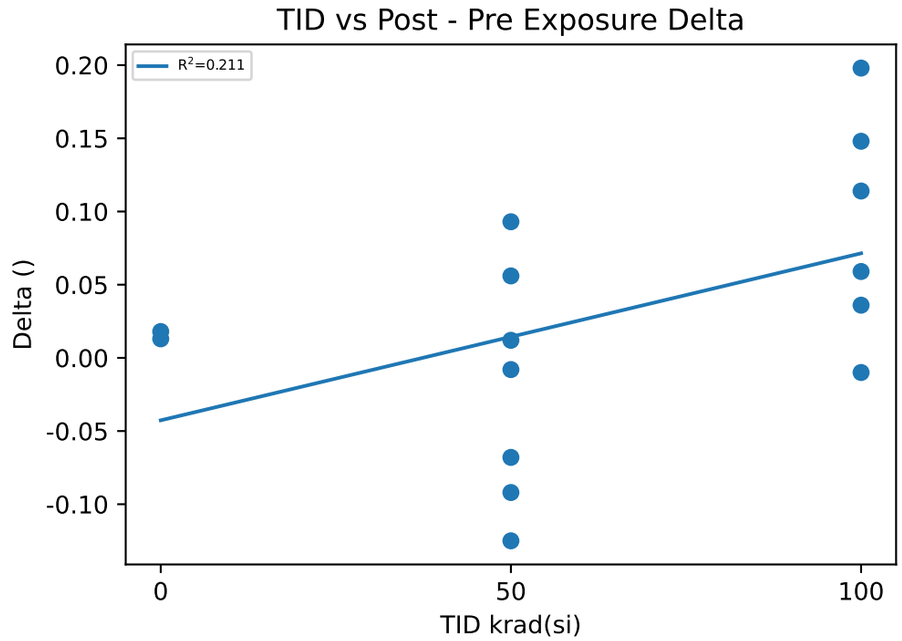
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.76	23.628	-0.132
89	50	Biased	23.961	24.147	0.186
90	50	Biased	23.823	23.816	-0.007
92	50	Biased	23.862	23.619	-0.243
93	50	Unbiased	23.508	23.547	0.039
94	50	Unbiased	23.804	23.697	-0.107
95	50	Unbiased	23.607	23.717	0.11
96	100	Biased	23.856	23.828	-0.028
97	100	Biased	23.743	24.01	0.267
98	100	Biased	23.774	23.776	0.002
99	100	Unbiased	24.134	24.18	0.046
100	100	Unbiased	23.721	23.849	0.128
101	100	Unbiased	23.765	23.953	0.188
102	0	Correlation	24.186	24.213	0.027
103	0	Correlation	24.23	24.192	-0.038

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.186	24.208	24.23	0.031113	24.192	24.203	24.213	0.014849	-0.038	-0.0055	0.027	0.045962
50	23.508	23.761	23.961	0.15471	23.547	23.739	24.147	0.19926	-0.243	-0.022	0.186	0.14877
100	23.721	23.832	24.134	0.15484	23.776	23.933	24.18	0.14837	-0.028	0.1005	0.267	0.1143

Device Test: 5.72 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB2_SD/RESETB2/7/3/1.18M/0/0/@DLY_TMR_1MOHM)





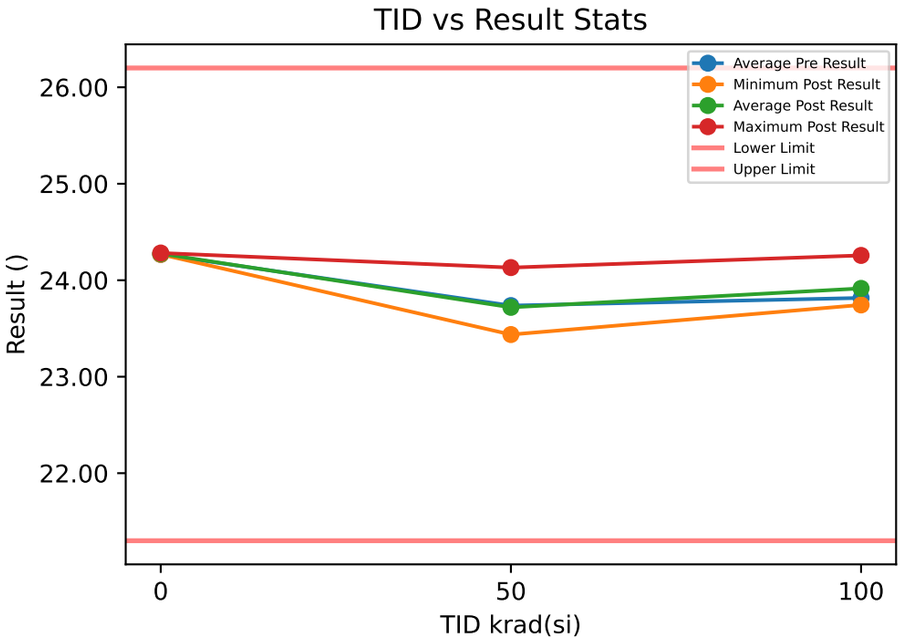
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

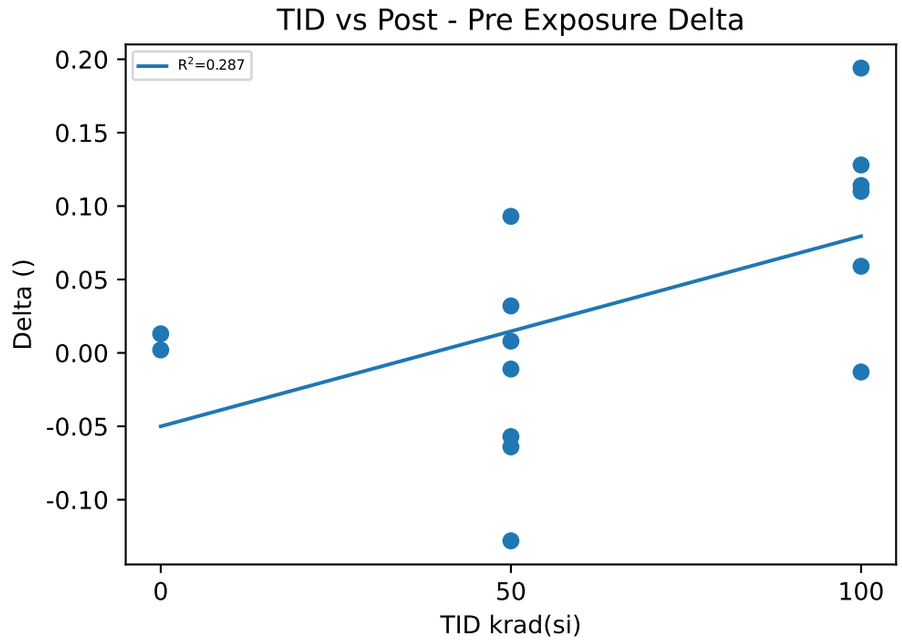
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.793	23.701	-0.092
89	50	Biased	24.029	24.122	0.093
90	50	Biased	23.771	23.703	-0.068
92	50	Biased	23.781	23.656	-0.125
93	50	Unbiased	23.377	23.433	0.056
94	50	Unbiased	23.733	23.725	-0.008
95	50	Unbiased	23.636	23.648	0.012
96	100	Biased	23.735	23.794	0.059
97	100	Biased	23.78	23.978	0.198
98	100	Biased	23.669	23.705	0.036
99	100	Unbiased	24.138	24.252	0.114
100	100	Unbiased	23.748	23.738	-0.01
101	100	Unbiased	23.757	23.905	0.148
102	0	Correlation	24.246	24.264	0.018
103	0	Correlation	24.27	24.283	0.013

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.246	24.258	24.27	0.016971	24.264	24.273	24.283	0.013435	0.013	0.0155	0.018	0.0035355
50	23.377	23.731	24.029	0.19625	23.433	23.713	24.122	0.20556	-0.125	-0.018857	0.093	0.079809
100	23.669	23.805	24.138	0.16761	23.705	23.895	24.252	0.20268	-0.01	0.090833	0.198	0.076781

Device Test: 5.73 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB4_SD/RESETB4/7/3/1.18M/0/0/@DLY_TMR_1MOHM)





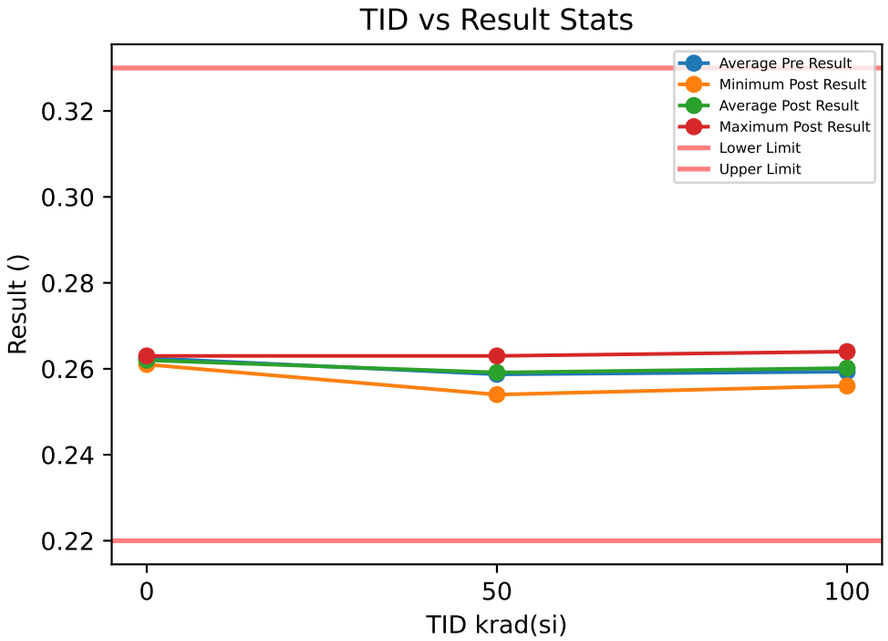
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

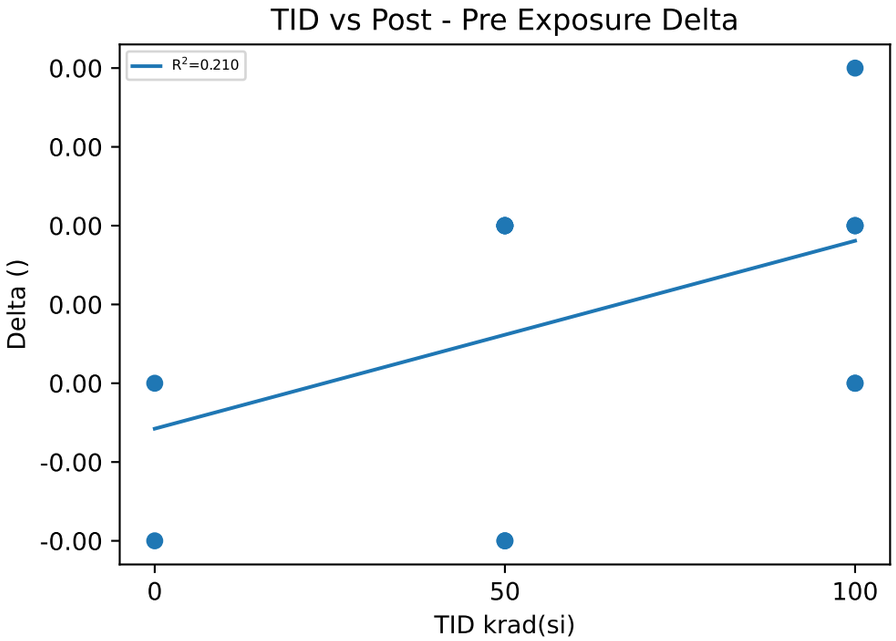
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.764	23.707	-0.057
89	50	Biased	24.038	24.131	0.093
90	50	Biased	23.776	23.712	-0.064
92	50	Biased	23.79	23.662	-0.128
93	50	Unbiased	23.405	23.437	0.032
94	50	Unbiased	23.742	23.731	-0.011
95	50	Unbiased	23.645	23.653	0.008
96	100	Biased	23.743	23.802	0.059
97	100	Biased	23.789	23.983	0.194
98	100	Biased	23.658	23.768	0.11
99	100	Unbiased	24.143	24.257	0.114
100	100	Unbiased	23.757	23.744	-0.013
101	100	Unbiased	23.809	23.937	0.128
102	0	Correlation	24.255	24.268	0.013
103	0	Correlation	24.28	24.282	0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.255	24.267	24.28	0.017678	24.268	24.275	24.282	0.0098995	0.002	0.0075	0.013	0.0077782
50	23.405	23.737	24.038	0.18902	23.437	23.719	24.131	0.20705	-0.128	-0.018143	0.093	0.072207
100	23.658	23.817	24.143	0.16821	23.744	23.915	24.257	0.19271	-0.013	0.098667	0.194	0.069793

Device Test: 5.74 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB1_SU/RESETB1/7/14/10.5K/0/0/@DLY_TMR_10KOHM)





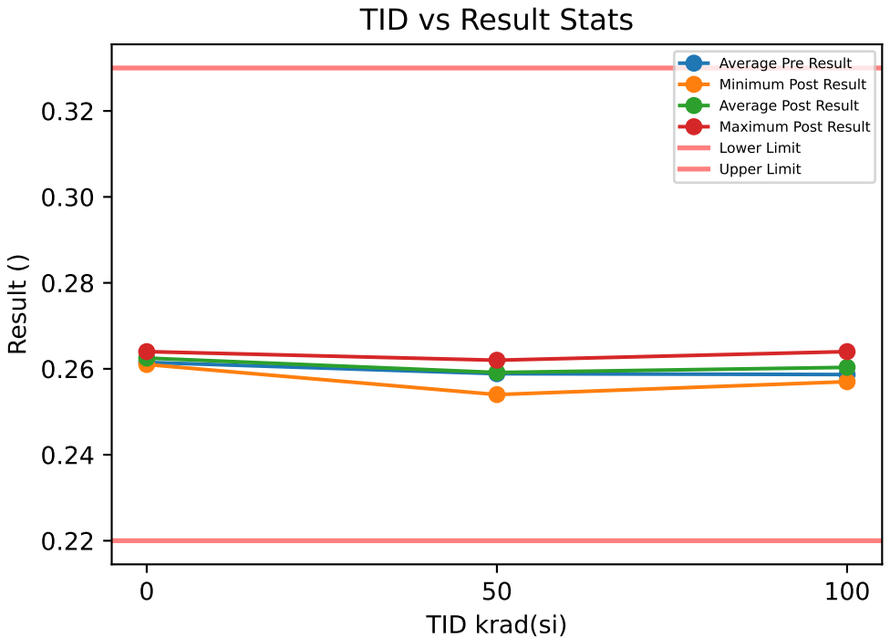
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

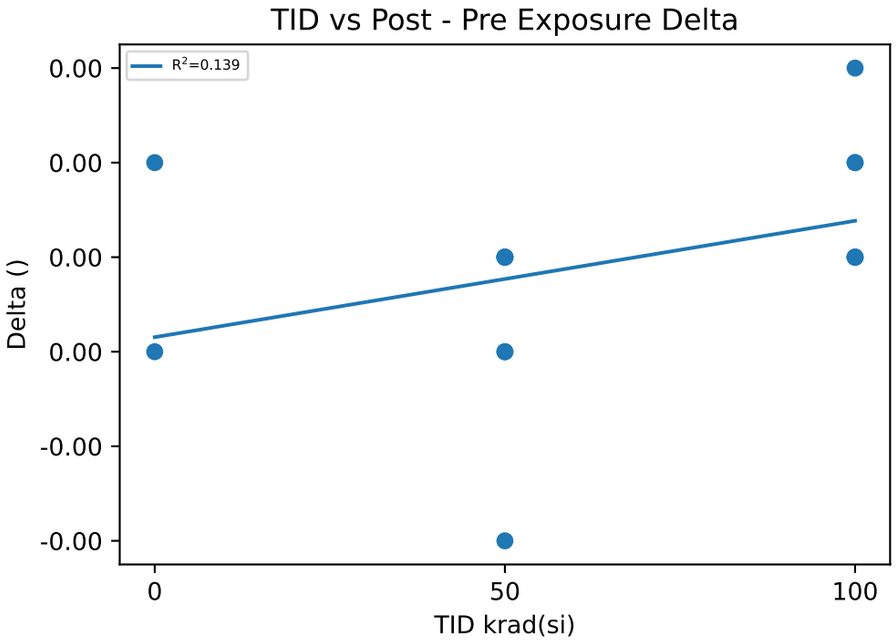
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.261	0.262	0.001
89	50	Biased	0.261	0.26	-0.001
90	50	Biased	0.253	0.254	0.001
92	50	Biased	0.261	0.26	-0.001
93	50	Unbiased	0.253	0.254	0.001
94	50	Unbiased	0.262	0.263	0.001
95	50	Unbiased	0.26	0.261	0.001
96	100	Biased	0.256	0.256	0
97	100	Biased	0.264	0.264	0
98	100	Biased	0.261	0.263	0.002
99	100	Unbiased	0.256	0.257	0.001
100	100	Unbiased	0.256	0.257	0.001
101	100	Unbiased	0.263	0.264	0.001
102	0	Correlation	0.263	0.263	0
103	0	Correlation	0.262	0.261	-0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.262	0.2625	0.263	0.00070711	0.261	0.262	0.263	0.0014142	-0.001	-0.0005	0	0.00070711
50	0.253	0.25871	0.262	0.0039461	0.254	0.25914	0.263	0.003671	-0.001	0.00042857	0.001	0.0009759
100	0.256	0.25933	0.264	0.0037771	0.256	0.26017	0.264	0.0038687	0	0.00083333	0.002	0.00075277

Device Test: 5.75 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB3_SU/RESETB3/7/14/10.5K/0/0/@DLY_TMR_10KOHM)





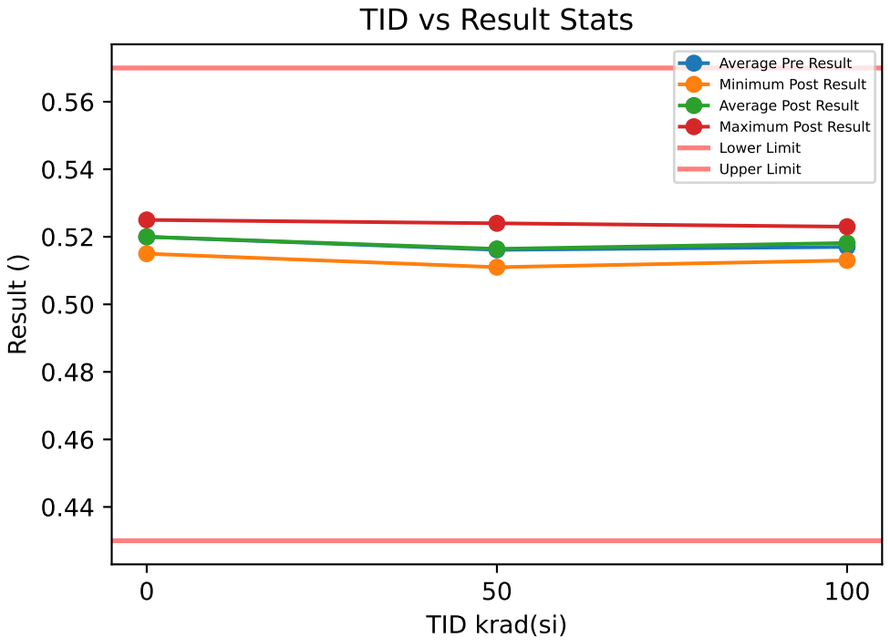
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

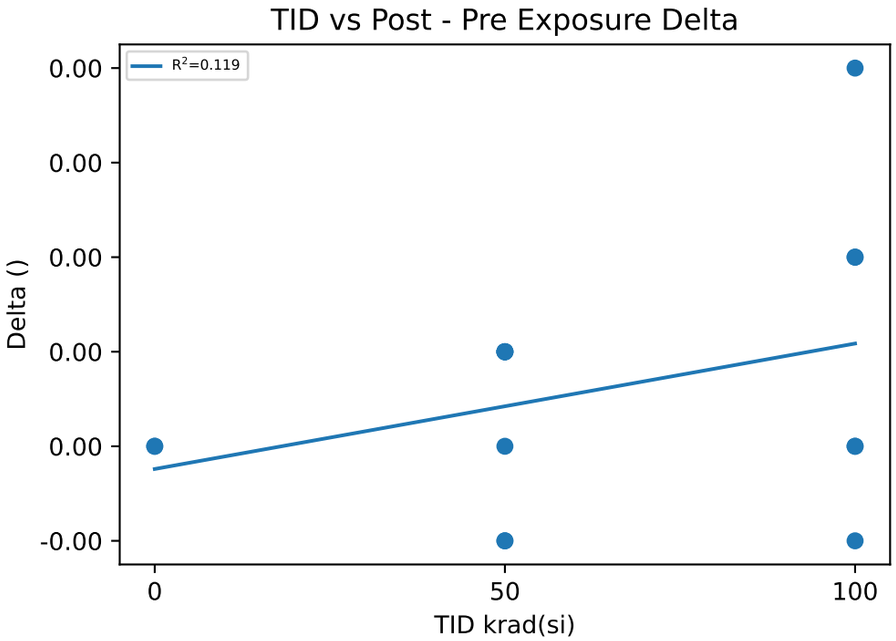
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.261	0.262	0.001
89	50	Biased	0.261	0.259	-0.002
90	50	Biased	0.253	0.254	0.001
92	50	Biased	0.261	0.261	0
93	50	Unbiased	0.253	0.254	0.001
94	50	Unbiased	0.262	0.262	0
95	50	Unbiased	0.261	0.262	0.001
96	100	Biased	0.256	0.257	0.001
97	100	Biased	0.263	0.264	0.001
98	100	Biased	0.261	0.262	0.001
99	100	Unbiased	0.256	0.258	0.002
100	100	Unbiased	0.255	0.257	0.002
101	100	Unbiased	0.261	0.264	0.003
102	0	Correlation	0.262	0.264	0.002
103	0	Correlation	0.261	0.261	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.261	0.2615	0.262	0.00070711	0.261	0.2625	0.264	0.0021213	0	0.001	0.002	0.0014142
50	0.253	0.25886	0.262	0.0040178	0.254	0.25914	0.262	0.003671	-0.002	0.00028571	0.001	0.0011127
100	0.255	0.25867	0.263	0.0033862	0.257	0.26033	0.264	0.0033862	0.001	0.0016667	0.003	0.0008165

Device Test: 5.76 WD_TMR_10KOHM(twd_Res10p5K_WDOB_SU/WDOB/7/14/10.5K/0/0/@WD_TMR_10KOHM)





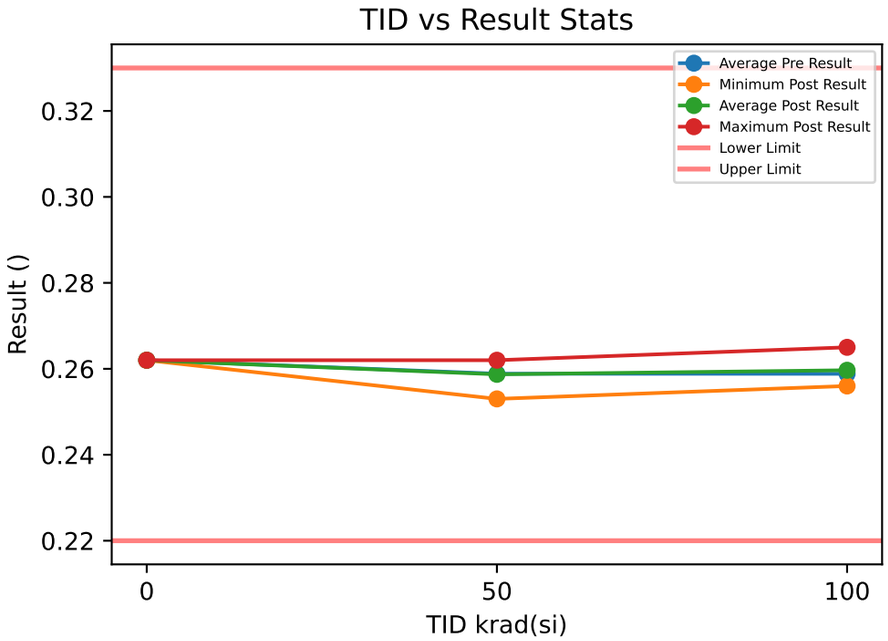
Test Results (Lower Limit = 0.43, Upper Limit = 0.57 ())

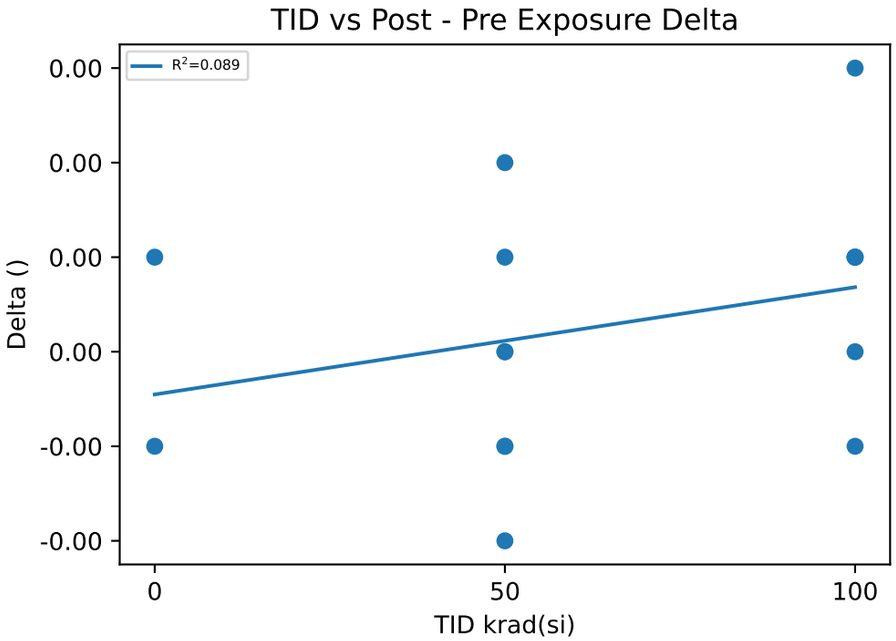
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.517	0.516	-0.001
89	50	Biased	0.51	0.511	0.001
90	50	Biased	0.512	0.513	0.001
92	50	Biased	0.519	0.52	0.001
93	50	Unbiased	0.512	0.513	0.001
94	50	Unbiased	0.524	0.524	0
95	50	Unbiased	0.519	0.518	-0.001
96	100	Biased	0.516	0.515	-0.001
97	100	Biased	0.52	0.52	0
98	100	Biased	0.513	0.513	0
99	100	Unbiased	0.519	0.523	0.004
100	100	Unbiased	0.515	0.517	0.002
101	100	Unbiased	0.519	0.521	0.002
102	0	Correlation	0.525	0.525	0
103	0	Correlation	0.515	0.515	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.515	0.52	0.525	0.0070711	0.515	0.52	0.525	0.0070711	0	0	0	0
50	0.51	0.51614	0.524	0.0050143	0.511	0.51643	0.524	0.0045774	-0.001	0.00028571	0.001	0.00095119
100	0.513	0.517	0.52	0.0027568	0.513	0.51817	0.523	0.0038166	-0.001	0.0011667	0.004	0.0018348

Device Test: 5.77 DLY_TMR_10KOHM(tdly_Res10p5K_PWRGD_SU/PWRGD/7/14/10.5K/0/0/@DLY_TMR_10KOHM)





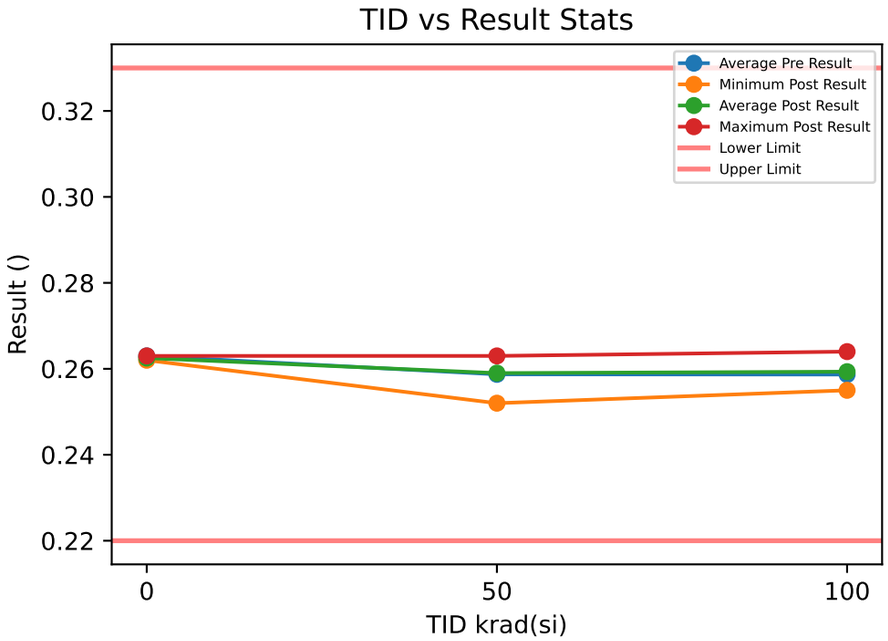
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

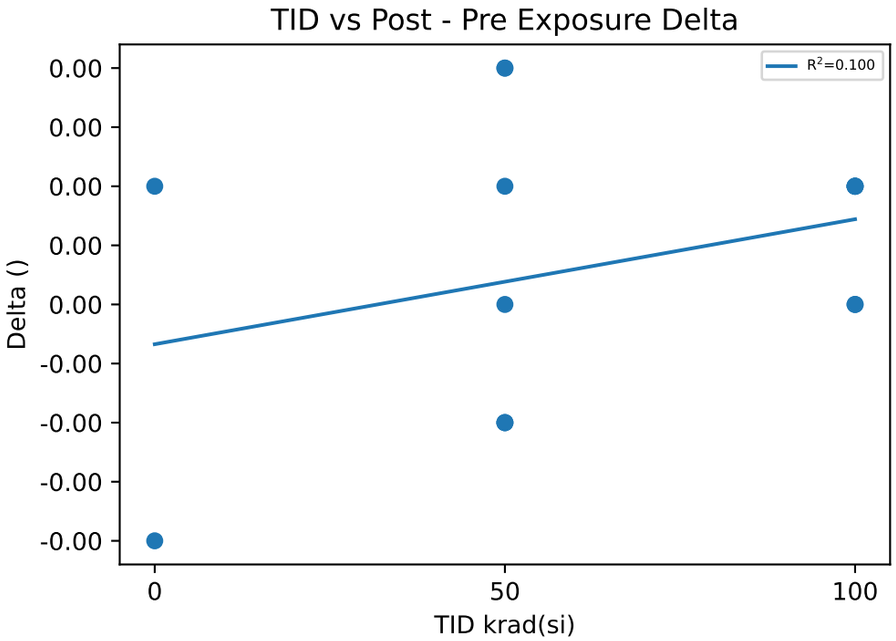
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.261	0.26	-0.001
89	50	Biased	0.261	0.259	-0.002
90	50	Biased	0.253	0.253	0
92	50	Biased	0.26	0.261	0.001
93	50	Unbiased	0.253	0.255	0.002
94	50	Unbiased	0.262	0.261	-0.001
95	50	Unbiased	0.262	0.262	0
96	100	Biased	0.255	0.256	0.001
97	100	Biased	0.262	0.265	0.003
98	100	Biased	0.262	0.261	-0.001
99	100	Unbiased	0.256	0.257	0.001
100	100	Unbiased	0.255	0.256	0.001
101	100	Unbiased	0.263	0.263	0
102	0	Correlation	0.263	0.262	-0.001
103	0	Correlation	0.261	0.262	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.261	0.262	0.263	0.0014142	0.262	0.262	0.262	0	-0.001	0	0.001	0.0014142
50	0.253	0.25886	0.262	0.0040591	0.253	0.25871	0.262	0.0034017	-0.002	-0.00014286	0.002	0.0013452
100	0.255	0.25883	0.263	0.0038687	0.256	0.25967	0.265	0.0038816	-0.001	0.00083333	0.003	0.0013292

Device Test: 5.78 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB2_SD/RESETB2/7/14/10.5K/0/0/@DLY_TMR_10KOHM)





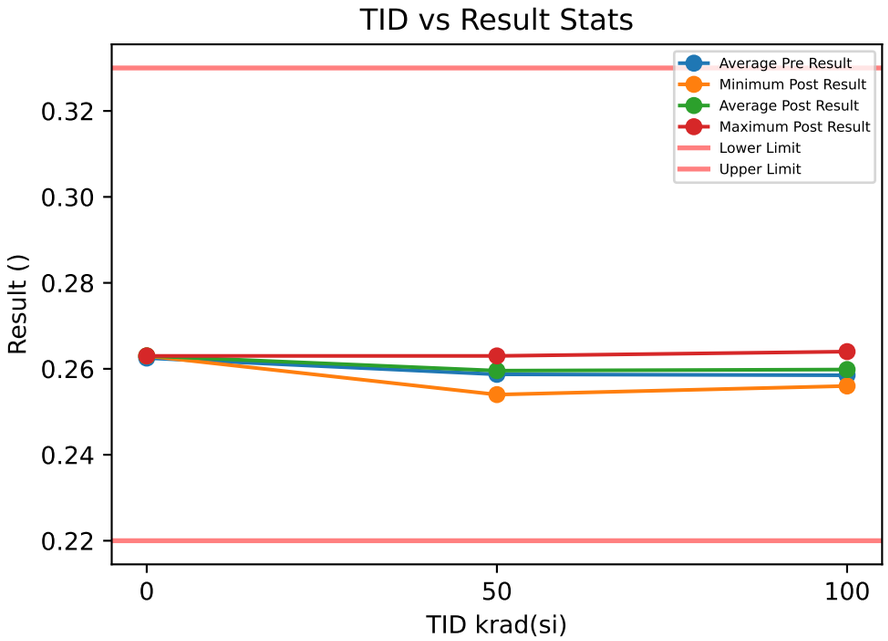
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

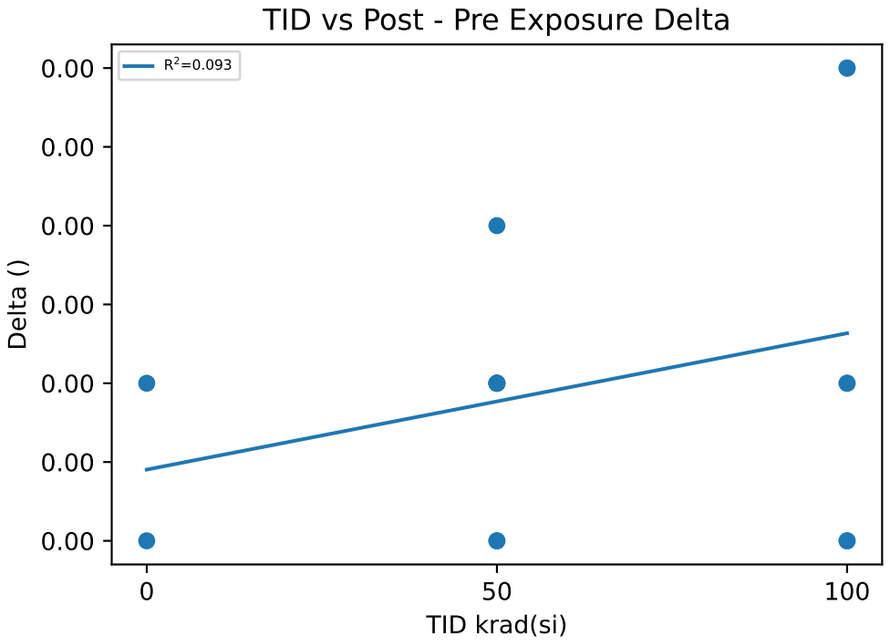
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.26	0.262	0.002
89	50	Biased	0.261	0.26	-0.001
90	50	Biased	0.253	0.252	-0.001
92	50	Biased	0.262	0.261	-0.001
93	50	Unbiased	0.253	0.254	0.001
94	50	Unbiased	0.261	0.263	0.002
95	50	Unbiased	0.261	0.261	0
96	100	Biased	0.255	0.256	0.001
97	100	Biased	0.264	0.264	0
98	100	Biased	0.261	0.261	0
99	100	Unbiased	0.256	0.257	0.001
100	100	Unbiased	0.254	0.255	0.001
101	100	Unbiased	0.262	0.263	0.001
102	0	Correlation	0.264	0.262	-0.002
103	0	Correlation	0.262	0.263	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.262	0.263	0.264	0.0014142	0.262	0.2625	0.263	0.00070711	-0.002	-0.0005	0.001	0.0021213
50	0.253	0.25871	0.262	0.0039461	0.252	0.259	0.263	0.0042426	-0.001	0.00028571	0.002	0.0013801
100	0.254	0.25867	0.264	0.0041793	0.255	0.25933	0.264	0.0038297	0	0.00066667	0.001	0.0005164

Device Test: 5.79 DLY_TMR_10KOHM(tdly_Res10p5K_RESETB4_SD/RESETB4/7/14/10.5K/0/0/@DLY_TMR_10KOHM)





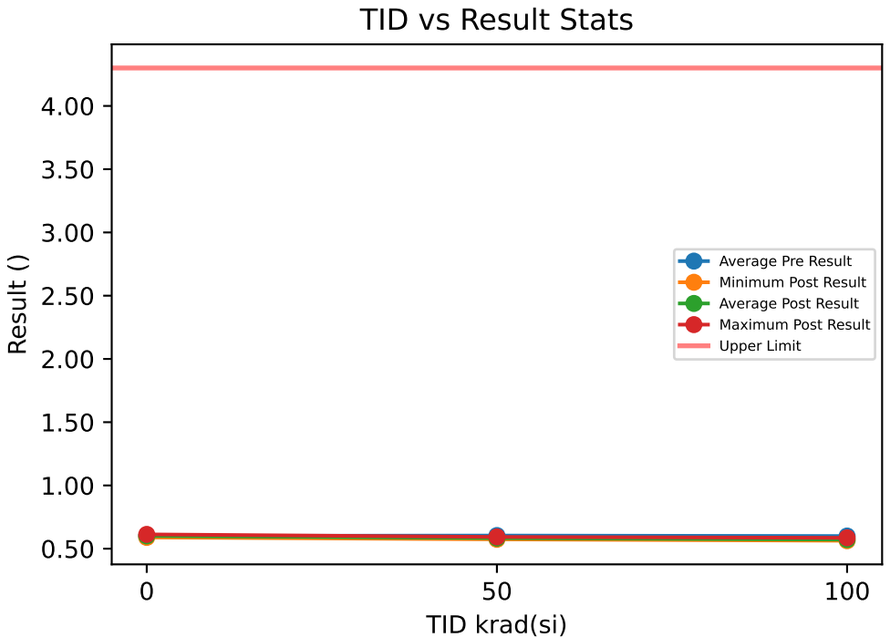
Test Results (Lower Limit = 0.22, Upper Limit = 0.33 ())

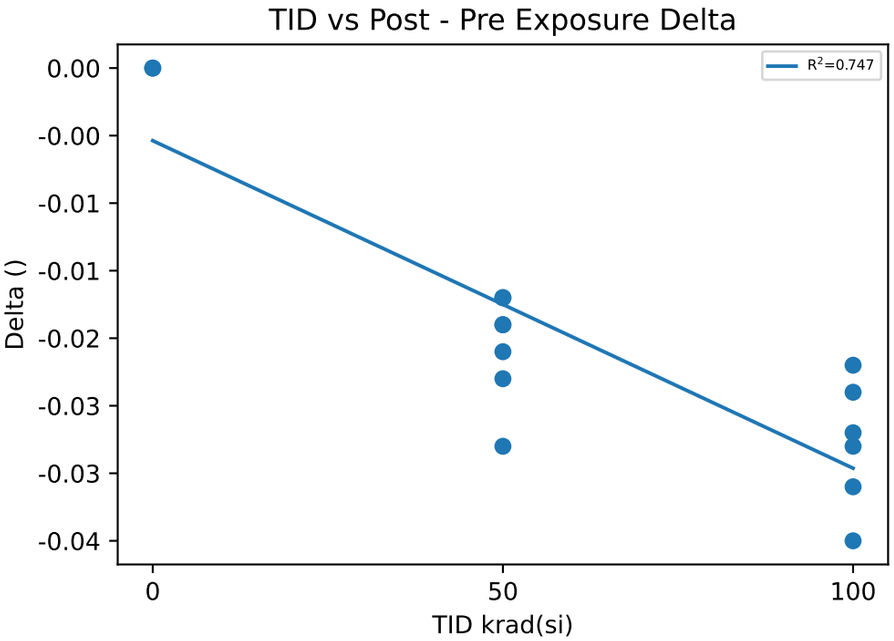
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.26	0.261	0.001
89	50	Biased	0.26	0.261	0.001
90	50	Biased	0.252	0.254	0.002
92	50	Biased	0.262	0.262	0
93	50	Unbiased	0.255	0.255	0
94	50	Unbiased	0.262	0.263	0.001
95	50	Unbiased	0.26	0.261	0.001
96	100	Biased	0.256	0.256	0
97	100	Biased	0.263	0.264	0.001
98	100	Biased	0.261	0.261	0
99	100	Unbiased	0.256	0.257	0.001
100	100	Unbiased	0.254	0.257	0.003
101	100	Unbiased	0.261	0.264	0.003
102	0	Correlation	0.263	0.263	0
103	0	Correlation	0.262	0.263	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.262	0.2625	0.263	0.00070711	0.263	0.263	0.263	0	0	0.0005	0.001	0.00070711
50	0.252	0.25871	0.262	0.0037733	0.254	0.25957	0.263	0.0035523	0	0.00085714	0.002	0.00069007
100	0.254	0.2585	0.263	0.0036194	0.256	0.25983	0.264	0.003656	0	0.0013333	0.003	0.0013663

Device Test: 5.8 PROPD_RESET(tpd_RESETB2_SD/RESETB2/1.6/14/0/0/0/@PROPD_RESET)





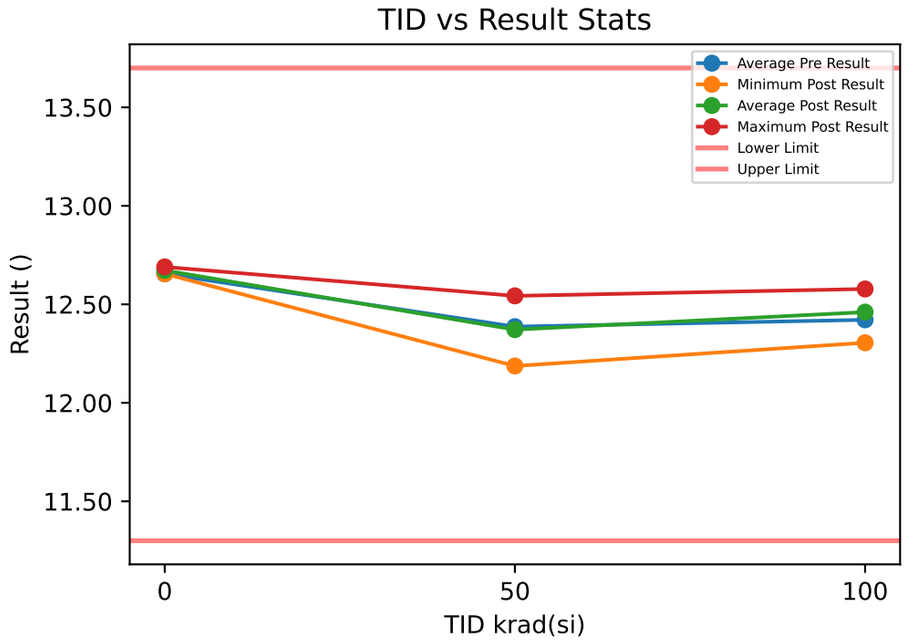
Test Results (Upper Limit = 4.3 ())

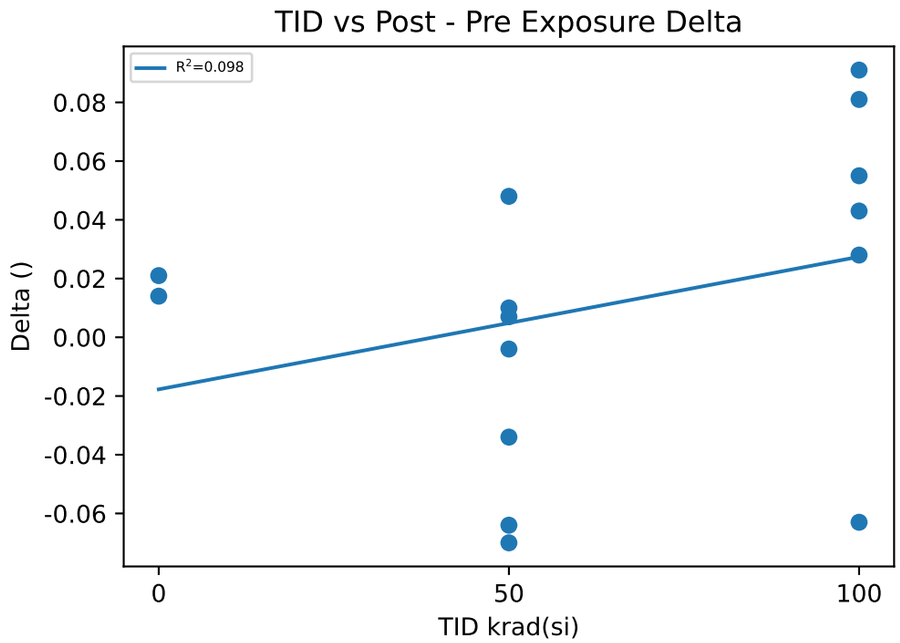
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.616	0.593	-0.023
89	50	Biased	0.598	0.581	-0.017
90	50	Biased	0.591	0.574	-0.017
92	50	Biased	0.598	0.579	-0.019
93	50	Unbiased	0.599	0.58	-0.019
94	50	Unbiased	0.613	0.585	-0.028
95	50	Unbiased	0.612	0.591	-0.021
96	100	Biased	0.595	0.564	-0.031
97	100	Biased	0.598	0.563	-0.035
98	100	Biased	0.592	0.57	-0.022
99	100	Unbiased	0.601	0.573	-0.028
100	100	Unbiased	0.61	0.586	-0.024
101	100	Unbiased	0.604	0.577	-0.027
102	0	Correlation	0.589	0.589	0
103	0	Correlation	0.613	0.613	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.589	0.601	0.613	0.016971	0.589	0.601	0.613	0.016971	0	0	0	0
50	0.591	0.60386	0.616	0.0096165	0.574	0.58329	0.593	0.0067999	-0.028	-0.020571	-0.017	0.0039097
100	0.592	0.6	0.61	0.0064807	0.563	0.57217	0.586	0.008612	-0.035	-0.027833	-0.022	0.0047081

Device Test: 5.80 DLY_TMR_500KOHM(tdly_Res619K_RESETB1_SU/RESETB1/7/14/619K/0/0/@DLY_TMR_500KOHM)





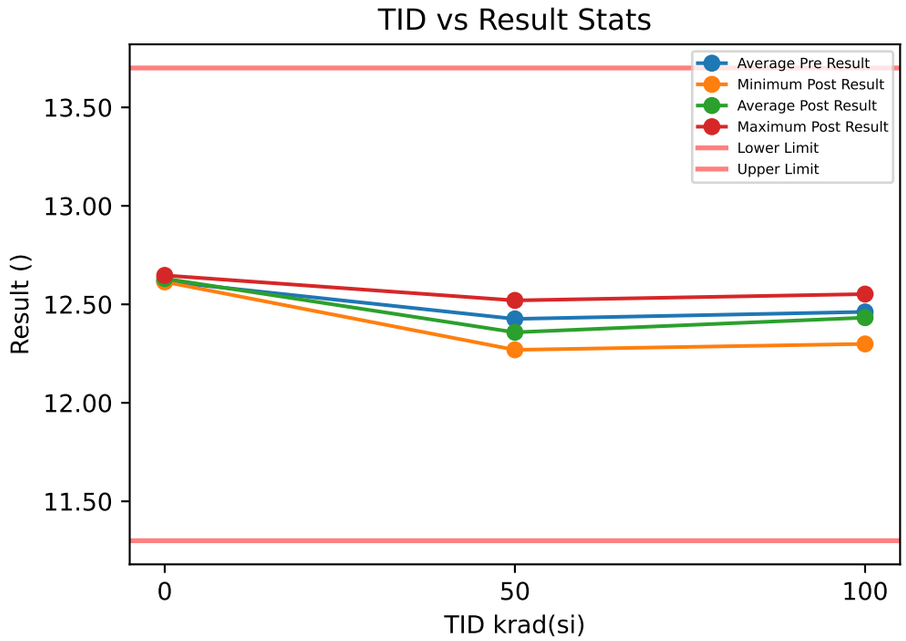
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

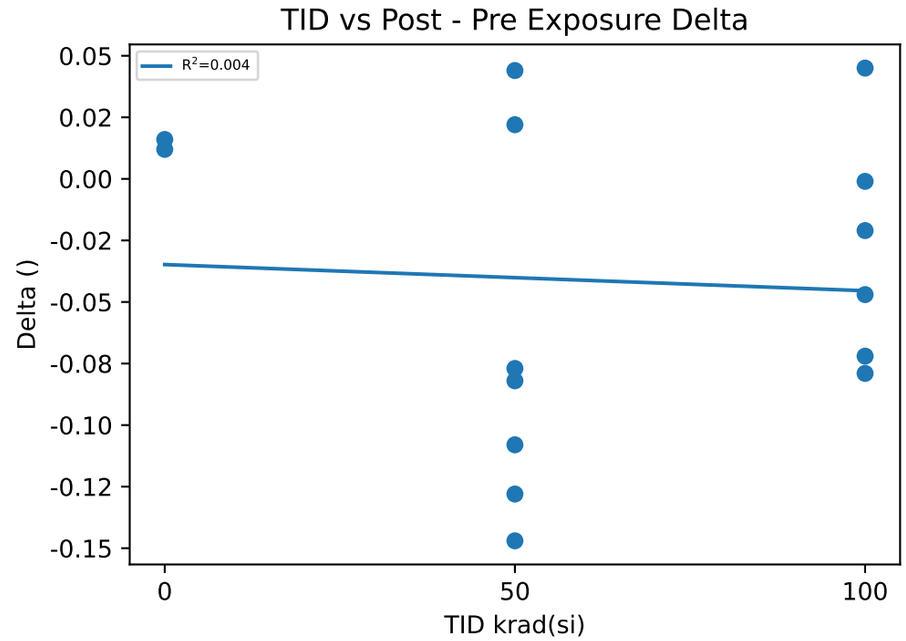
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.443	12.409	-0.034
89	50	Biased	12.495	12.543	0.048
90	50	Biased	12.381	12.317	-0.064
92	50	Biased	12.384	12.391	0.007
93	50	Unbiased	12.257	12.187	-0.07
94	50	Unbiased	12.406	12.416	0.01
95	50	Unbiased	12.342	12.338	-0.004
96	100	Biased	12.369	12.397	0.028
97	100	Biased	12.43	12.521	0.091
98	100	Biased	12.391	12.446	0.055
99	100	Unbiased	12.535	12.578	0.043
100	100	Unbiased	12.368	12.305	-0.063
101	100	Unbiased	12.435	12.516	0.081
102	0	Correlation	12.641	12.655	0.014
103	0	Correlation	12.669	12.69	0.021

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.641	12.655	12.669	0.019799	12.655	12.672	12.69	0.024749	0.014	0.0175	0.021	0.0049497
50	12.257	12.387	12.495	0.075422	12.187	12.372	12.543	0.10902	-0.07	-0.015286	0.048	0.042789
100	12.368	12.421	12.535	0.062746	12.305	12.461	12.578	0.098964	-0.063	0.039167	0.091	0.055254

Device Test: 5.81 DLY_TMR_500KOHM(tdly_Res619K_RESETB3_SU/RESETB3/7/14/619K/0/0/@DLY_TMR_500KOHM)





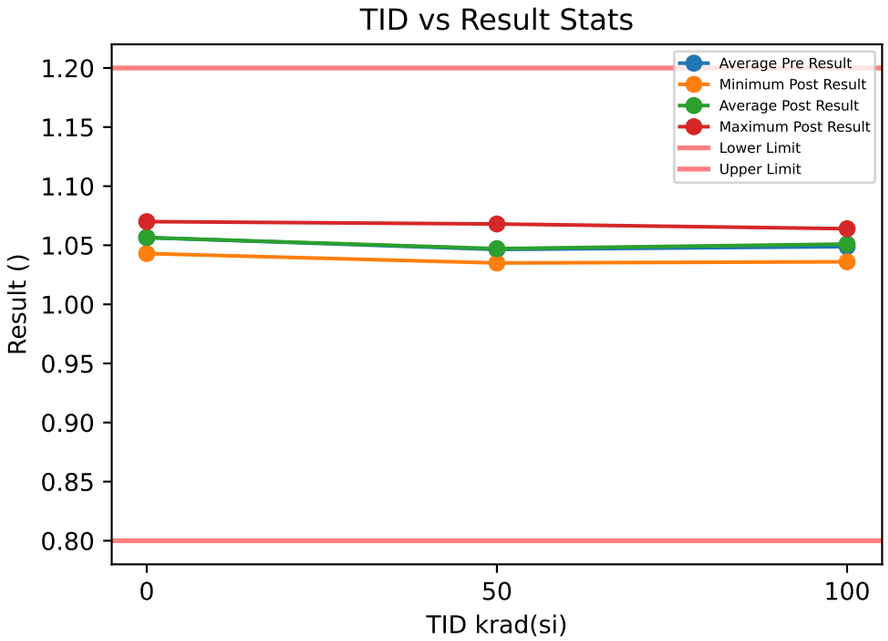
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

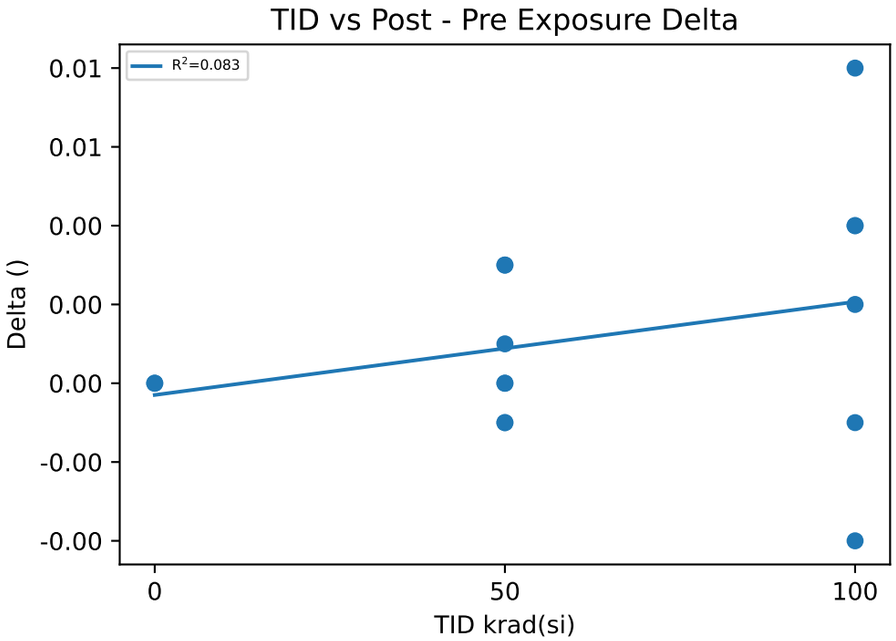
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.513	12.385	-0.128
89	50	Biased	12.476	12.52	0.044
90	50	Biased	12.377	12.269	-0.108
92	50	Biased	12.472	12.325	-0.147
93	50	Unbiased	12.252	12.274	0.022
94	50	Unbiased	12.473	12.391	-0.082
95	50	Unbiased	12.42	12.343	-0.077
96	100	Biased	12.392	12.32	-0.072
97	100	Biased	12.512	12.511	-0.001
98	100	Biased	12.465	12.418	-0.047
99	100	Unbiased	12.507	12.552	0.045
100	100	Unbiased	12.378	12.299	-0.079
101	100	Unbiased	12.516	12.495	-0.021
102	0	Correlation	12.598	12.614	0.016
103	0	Correlation	12.635	12.647	0.012

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.598	12.617	12.635	0.026163	12.614	12.631	12.647	0.023335	0.012	0.014	0.016	0.0028284
50	12.252	12.426	12.513	0.088607	12.269	12.358	12.52	0.085978	-0.147	-0.068	0.044	0.073442
100	12.378	12.462	12.516	0.062298	12.299	12.432	12.552	0.10492	-0.079	-0.029167	0.045	0.046897

Device Test: 5.82 WD_TMR_500KOHM(twd_Res619K_WDOB_SU/WDOB/7/14/619K/0/0/@WD_TMR_500KOHM)





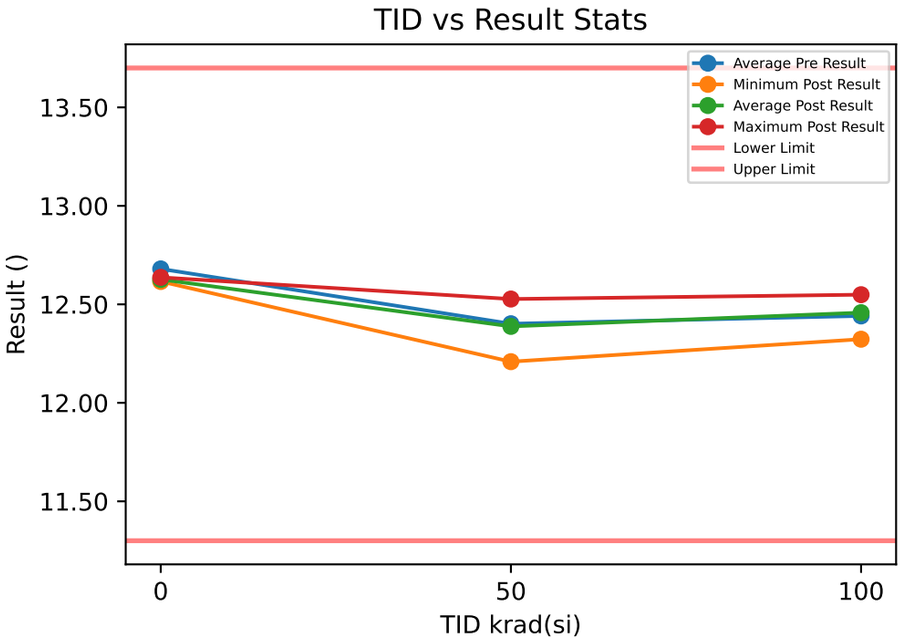
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 ())

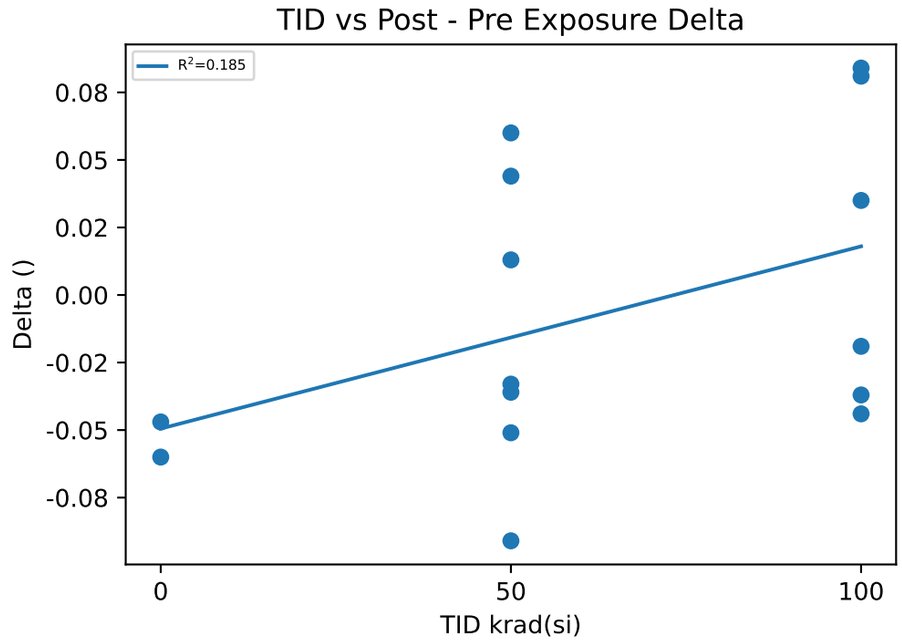
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.047	1.046	-0.001
89	50	Biased	1.032	1.035	0.003
90	50	Biased	1.035	1.036	0.001
92	50	Biased	1.056	1.056	0
93	50	Unbiased	1.034	1.037	0.003
94	50	Unbiased	1.068	1.068	0
95	50	Unbiased	1.053	1.052	-0.001
96	100	Biased	1.047	1.043	-0.004
97	100	Biased	1.054	1.056	0.002
98	100	Biased	1.037	1.036	-0.001
99	100	Unbiased	1.056	1.064	0.008
100	100	Unbiased	1.043	1.047	0.004
101	100	Unbiased	1.056	1.06	0.004
102	0	Correlation	1.07	1.07	0
103	0	Correlation	1.043	1.043	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.043	1.0565	1.07	0.019092	1.043	1.0565	1.07	0.019092	0	0	0	0
50	1.032	1.0464	1.068	0.013501	1.035	1.0471	1.068	0.012335	-0.001	0.00071429	0.003	0.0017043
100	1.037	1.0488	1.056	0.0078337	1.036	1.051	1.064	0.01077	-0.004	0.0021667	0.008	0.0042151

Device Test: 5.83 DLY_TMR_500KOHM(tdly_Res619K_PWRGD_SU/PWRGD/7/14/619K/0/0/@DLY_TMR_500KOHM)





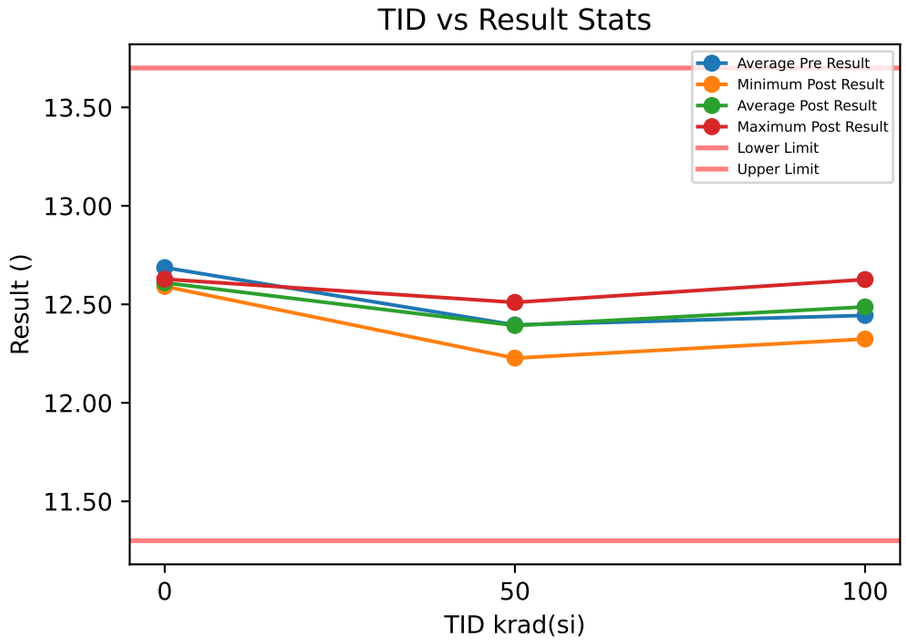
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

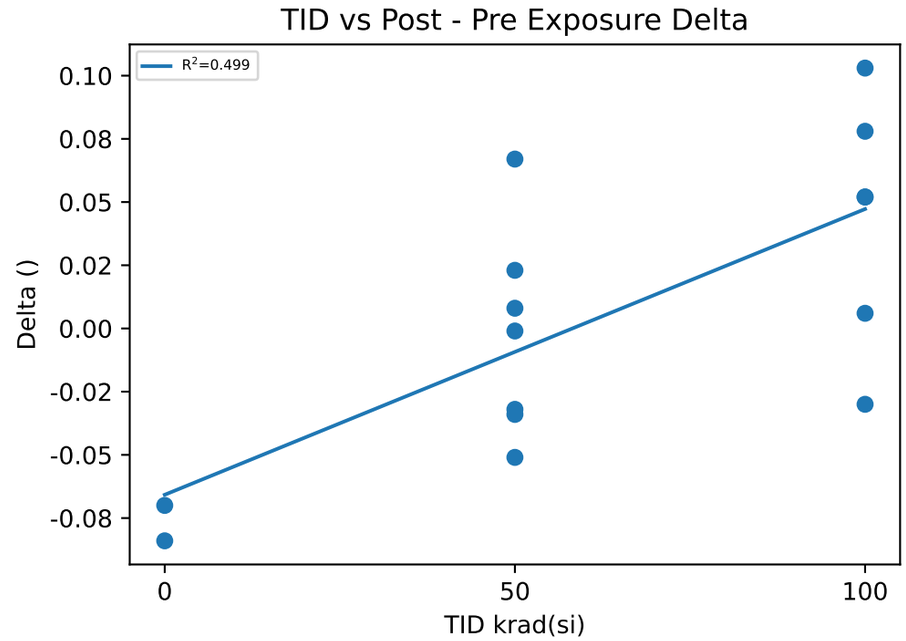
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.511	12.42	-0.091
89	50	Biased	12.483	12.527	0.044
90	50	Biased	12.317	12.33	0.013
92	50	Biased	12.405	12.372	-0.033
93	50	Unbiased	12.26	12.209	-0.051
94	50	Unbiased	12.465	12.429	-0.036
95	50	Unbiased	12.37	12.43	0.06
96	100	Biased	12.391	12.347	-0.044
97	100	Biased	12.433	12.514	0.081
98	100	Biased	12.448	12.483	0.035
99	100	Unbiased	12.55	12.531	-0.019
100	100	Unbiased	12.36	12.323	-0.037
101	100	Unbiased	12.465	12.549	0.084
102	0	Correlation	12.663	12.616	-0.047
103	0	Correlation	12.697	12.637	-0.06

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.663	12.68	12.697	0.024042	12.616	12.627	12.637	0.014849	-0.06	-0.0535	-0.047	0.0091924
50	12.26	12.402	12.511	0.092043	12.209	12.388	12.527	0.099541	-0.091	-0.013429	0.06	0.054329
100	12.36	12.441	12.55	0.065774	12.323	12.458	12.549	0.097895	-0.044	0.016667	0.084	0.058037

Device Test: 5.84 DLY_TMR_500KOHM(tdly_Res619K_RESETB2_SD/RESETB2/7/14/619K/0/0/@DLY_TMR_500KOHM)





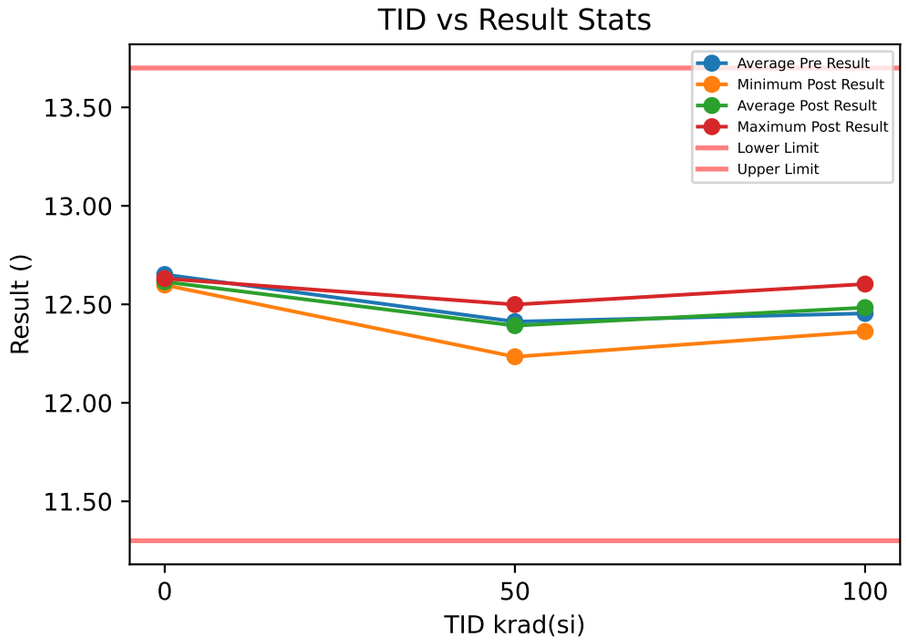
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

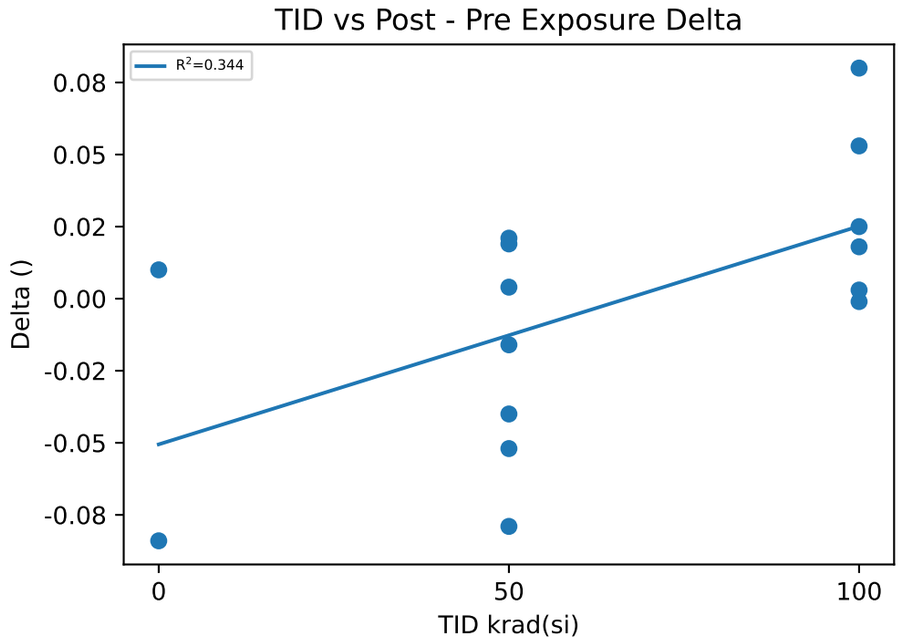
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.479	12.447	-0.032
89	50	Biased	12.544	12.51	-0.034
90	50	Biased	12.326	12.325	-0.001
92	50	Biased	12.435	12.384	-0.051
93	50	Unbiased	12.204	12.227	0.023
94	50	Unbiased	12.445	12.453	0.008
95	50	Unbiased	12.335	12.402	0.067
96	100	Biased	12.341	12.347	0.006
97	100	Biased	12.479	12.582	0.103
98	100	Biased	12.43	12.482	0.052
99	100	Unbiased	12.574	12.626	0.052
100	100	Unbiased	12.354	12.324	-0.03
101	100	Unbiased	12.484	12.562	0.078
102	0	Correlation	12.661	12.591	-0.07
103	0	Correlation	12.712	12.628	-0.084

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.661	12.686	12.712	0.036062	12.591	12.61	12.628	0.026163	-0.084	-0.077	-0.07	0.0098995
50	12.204	12.395	12.544	0.11416	12.227	12.393	12.51	0.093582	-0.051	-0.0028571	0.067	0.040429
100	12.341	12.444	12.574	0.087897	12.324	12.487	12.626	0.12662	-0.03	0.0435	0.103	0.048339

Device Test: 5.85 DLY_TMR_500KOHM(tdly_Res619K_RESETB4_SD/RESETB4/7/14/619K/0/0/@DLY_TMR_500KOHM)





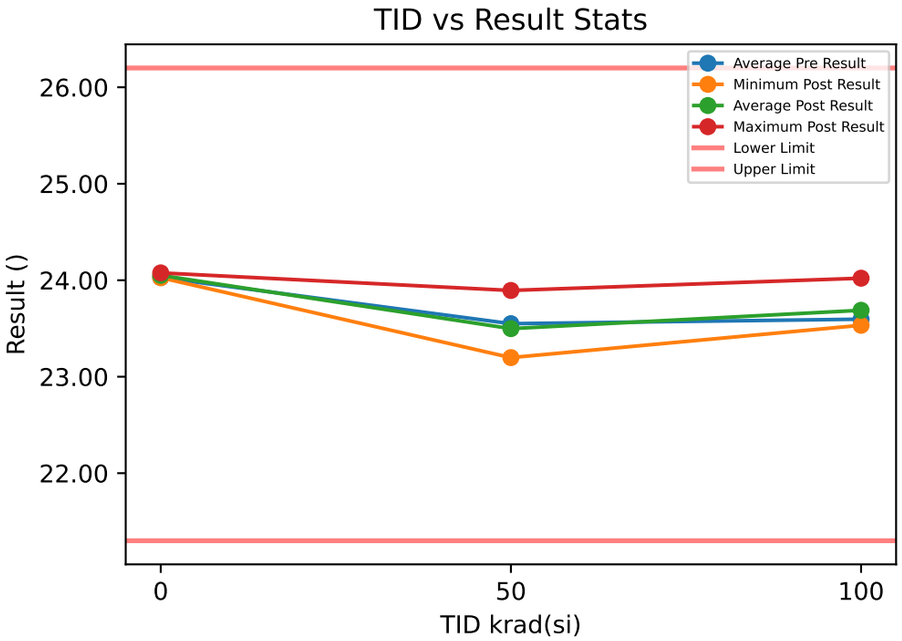
Test Results (Lower Limit = 11.3, Upper Limit = 13.7 ())

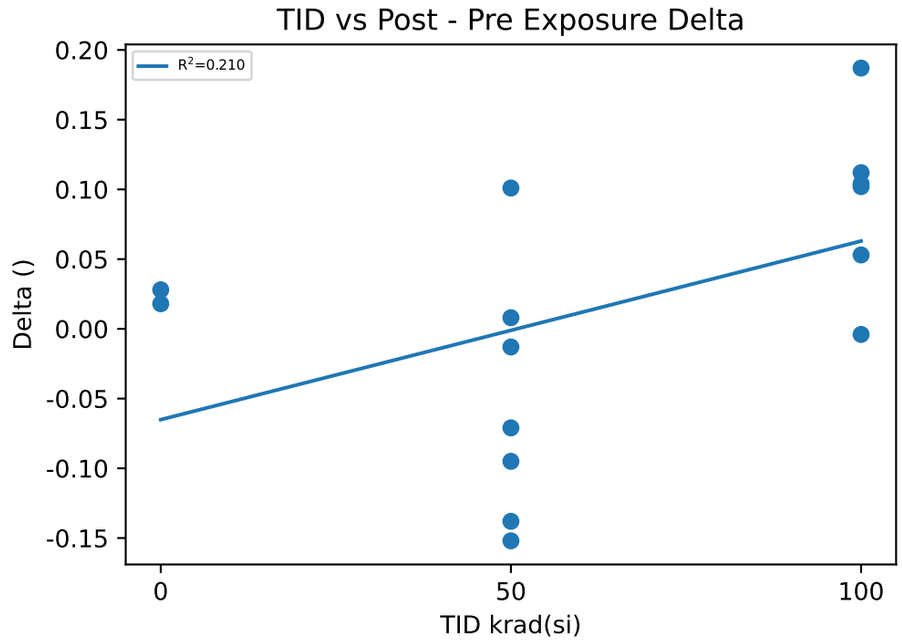
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.488	12.448	-0.04
89	50	Biased	12.551	12.499	-0.052
90	50	Biased	12.344	12.328	-0.016
92	50	Biased	12.446	12.367	-0.079
93	50	Unbiased	12.213	12.234	0.021
94	50	Unbiased	12.455	12.459	0.004
95	50	Unbiased	12.389	12.408	0.019
96	100	Biased	12.36	12.385	0.025
97	100	Biased	12.488	12.491	0.003
98	100	Biased	12.436	12.489	0.053
99	100	Unbiased	12.585	12.603	0.018
100	100	Unbiased	12.363	12.362	-0.001
101	100	Unbiased	12.491	12.571	0.08
102	0	Correlation	12.682	12.598	-0.084
103	0	Correlation	12.621	12.631	0.01

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.621	12.652	12.682	0.043134	12.598	12.614	12.631	0.023335	-0.084	-0.037	0.01	0.066468
50	12.213	12.412	12.551	0.11019	12.234	12.392	12.499	0.090383	-0.079	-0.020429	0.021	0.038074
100	12.36	12.454	12.585	0.086171	12.362	12.483	12.603	0.096424	-0.001	0.029667	0.08	0.031264

Device Test: 5.86 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB1_SU/RESETB1/7/14/1.18M/0/0/@DLY_TMR_1MOHM)





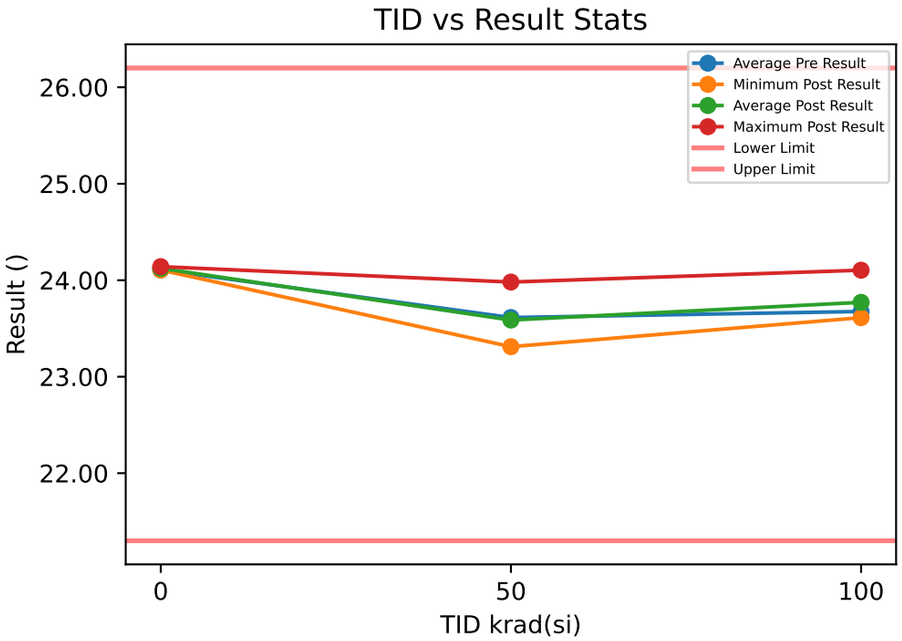
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

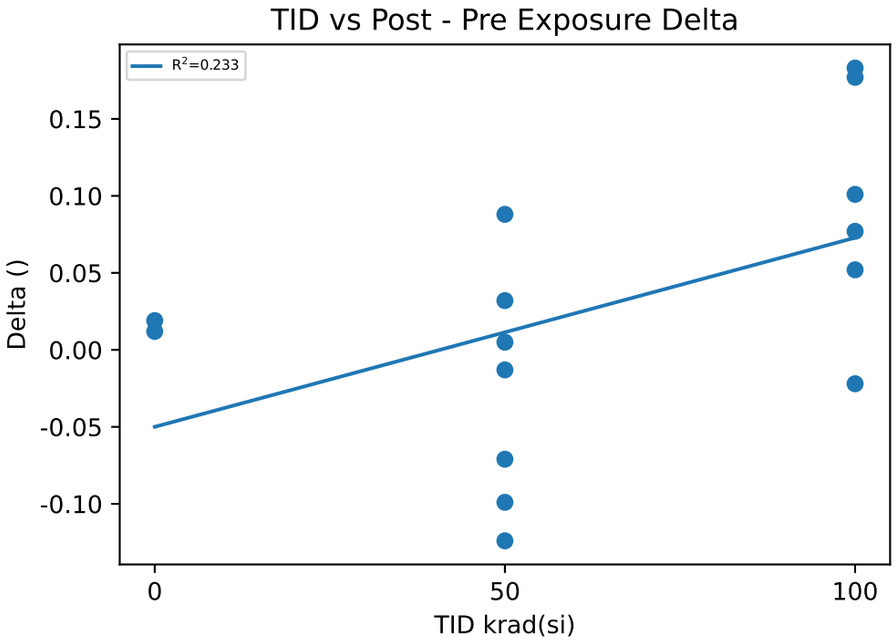
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.594	23.499	-0.095
89	50	Biased	23.793	23.894	0.101
90	50	Biased	23.583	23.512	-0.071
92	50	Biased	23.558	23.42	-0.138
93	50	Unbiased	23.35	23.198	-0.152
94	50	Unbiased	23.535	23.522	-0.013
95	50	Unbiased	23.435	23.443	0.008
96	100	Biased	23.53	23.583	0.053
97	100	Biased	23.57	23.757	0.187
98	100	Biased	23.423	23.535	0.112
99	100	Unbiased	23.917	24.021	0.104
100	100	Unbiased	23.537	23.533	-0.004
101	100	Unbiased	23.6	23.702	0.102
102	0	Correlation	24.008	24.026	0.018
103	0	Correlation	24.048	24.076	0.028

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.008	24.028	24.048	0.028284	24.026	24.051	24.076	0.035355	0.018	0.023	0.028	0.0070711
50	23.35	23.55	23.793	0.1388	23.198	23.498	23.894	0.20684	-0.152	-0.051429	0.101	0.089567
100	23.423	23.596	23.917	0.16823	23.533	23.689	24.021	0.18671	-0.004	0.092333	0.187	0.063883

Device Test: 5.87 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB3_SU/RESETB3/7/14/1.18M/0/0/@DLY_TMR_1MOHM)





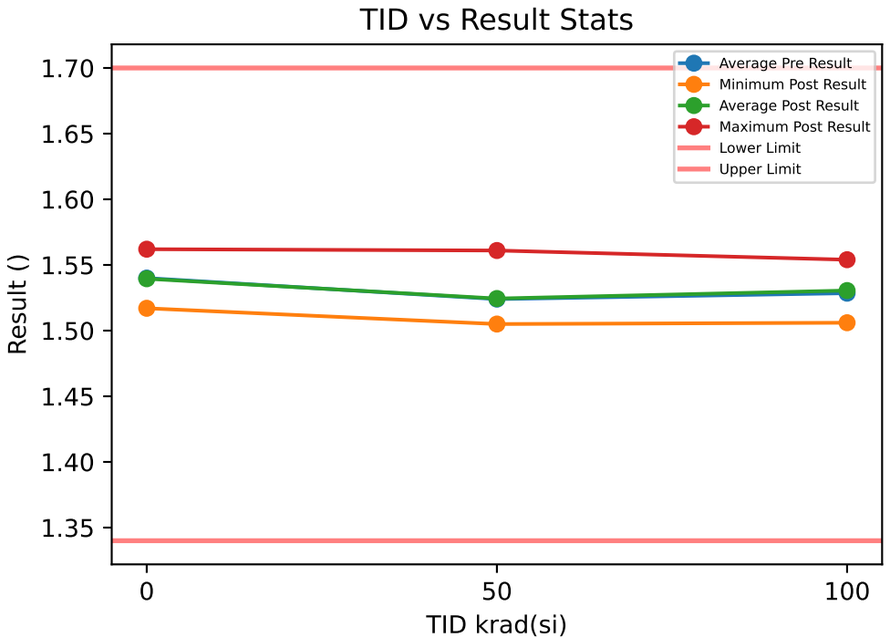
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

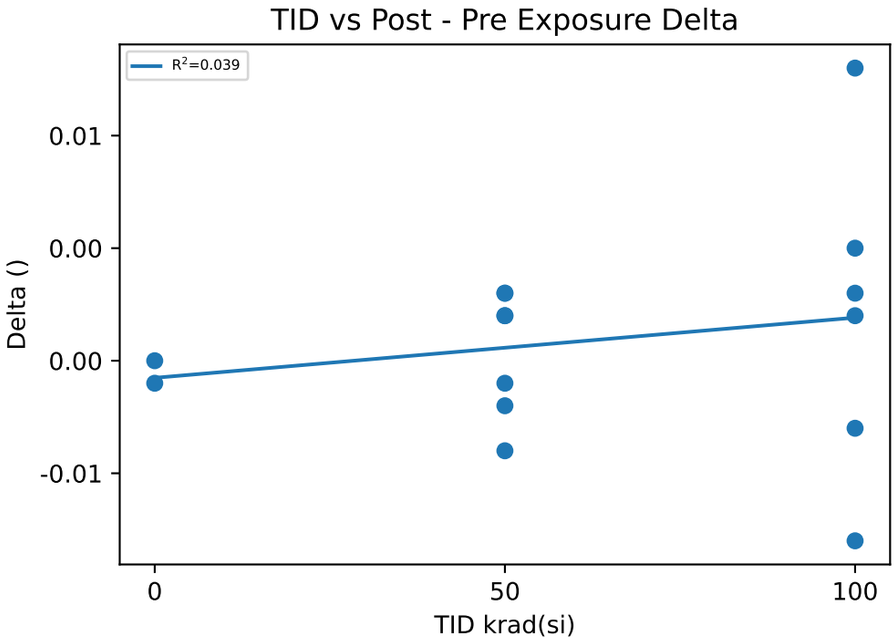
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.675	23.576	-0.099
89	50	Biased	23.893	23.981	0.088
90	50	Biased	23.662	23.591	-0.071
92	50	Biased	23.653	23.529	-0.124
93	50	Unbiased	23.279	23.311	0.032
94	50	Unbiased	23.613	23.6	-0.013
95	50	Unbiased	23.518	23.523	0.005
96	100	Biased	23.609	23.661	0.052
97	100	Biased	23.647	23.83	0.183
98	100	Biased	23.536	23.613	0.077
99	100	Unbiased	24.003	24.104	0.101
100	100	Unbiased	23.634	23.612	-0.022
101	100	Unbiased	23.628	23.805	0.177
102	0	Correlation	24.087	24.106	0.019
103	0	Correlation	24.129	24.141	0.012

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.087	24.108	24.129	0.029698	24.106	24.123	24.141	0.024749	0.012	0.0155	0.019	0.0049497
50	23.279	23.613	23.893	0.18566	23.311	23.587	23.981	0.19966	-0.124	-0.026	0.088	0.075772
100	23.536	23.676	24.003	0.16488	23.612	23.771	24.104	0.18861	-0.022	0.094667	0.183	0.07793

Device Test: 5.88 WD_TMR_1MOHM(twd_Res1p18M_WDOB_SU/WDOB/7/14/1.18M/0/0/@WD_TMR_1MOHM)





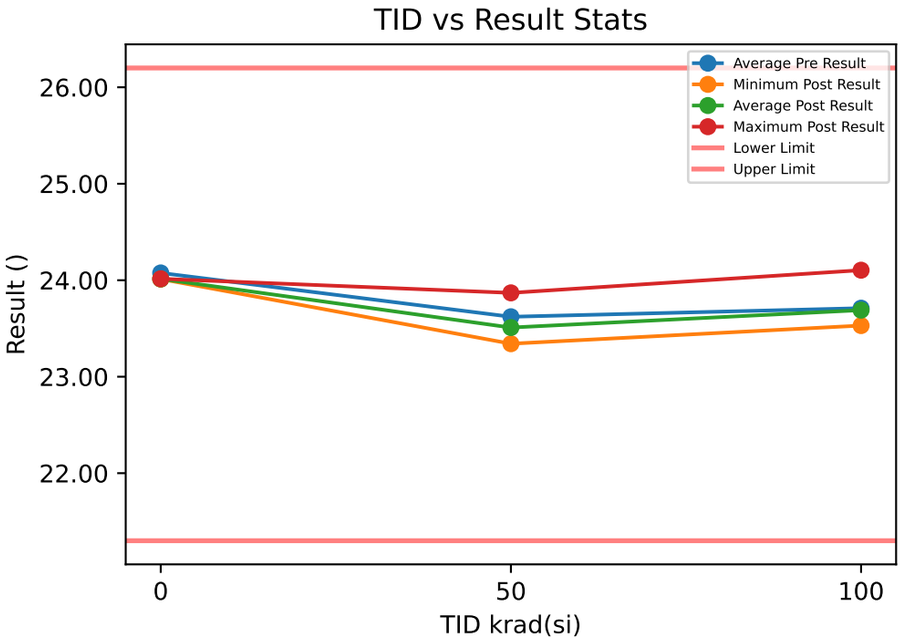
Test Results (Lower Limit = 1.34, Upper Limit = 1.7 ())

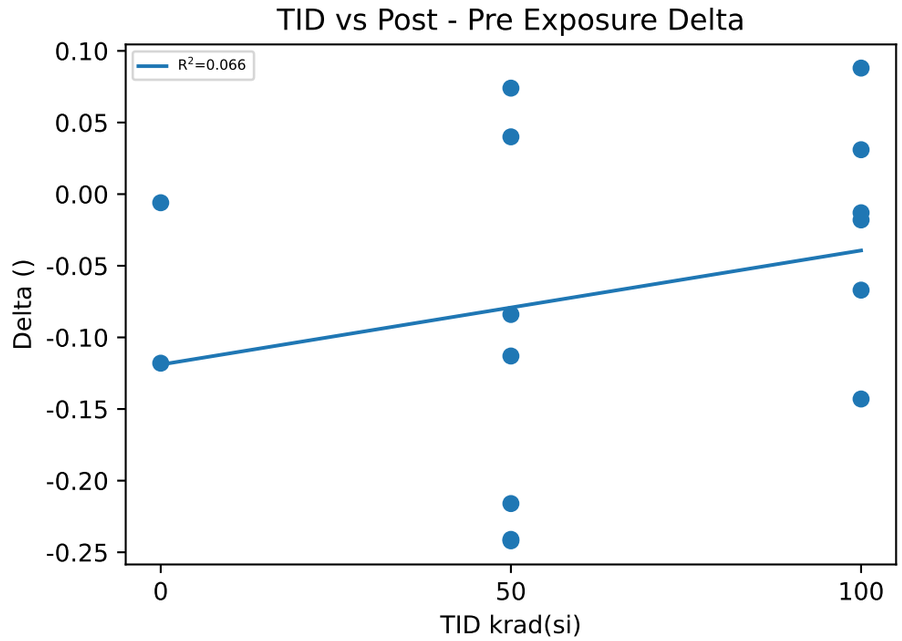
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.525	1.521	-0.004
89	50	Biased	1.502	1.505	0.003
90	50	Biased	1.503	1.505	0.002
92	50	Biased	1.539	1.541	0.002
93	50	Unbiased	1.503	1.506	0.003
94	50	Unbiased	1.562	1.561	-0.001
95	50	Unbiased	1.534	1.532	-0.002
96	100	Biased	1.525	1.517	-0.008
97	100	Biased	1.537	1.539	0.002
98	100	Biased	1.509	1.506	-0.003
99	100	Unbiased	1.541	1.554	0.013
100	100	Unbiased	1.519	1.522	0.003
101	100	Unbiased	1.54	1.545	0.005
102	0	Correlation	1.562	1.562	0
103	0	Correlation	1.518	1.517	-0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.518	1.54	1.562	0.031113	1.517	1.5395	1.562	0.03182	-0.001	-0.0005	0	0.00070711
50	1.502	1.524	1.562	0.022862	1.505	1.5244	1.561	0.021509	-0.004	0.00042857	0.003	0.0027603
100	1.509	1.5285	1.541	0.012988	1.506	1.5305	1.554	0.018382	-0.008	0.002	0.013	0.0071554

Device Test: 5.89 DLY_TMR_1MOHM(tdly_Res1p18M_PWRGD_SU/PWRGD/7/14/1.18M/0/0/@DLY_TMR_1MOHM)





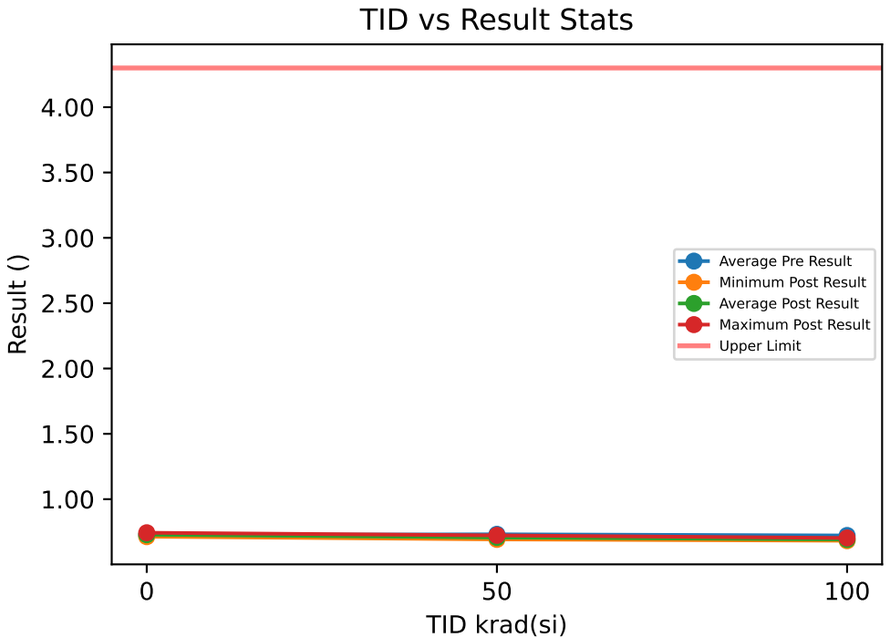
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

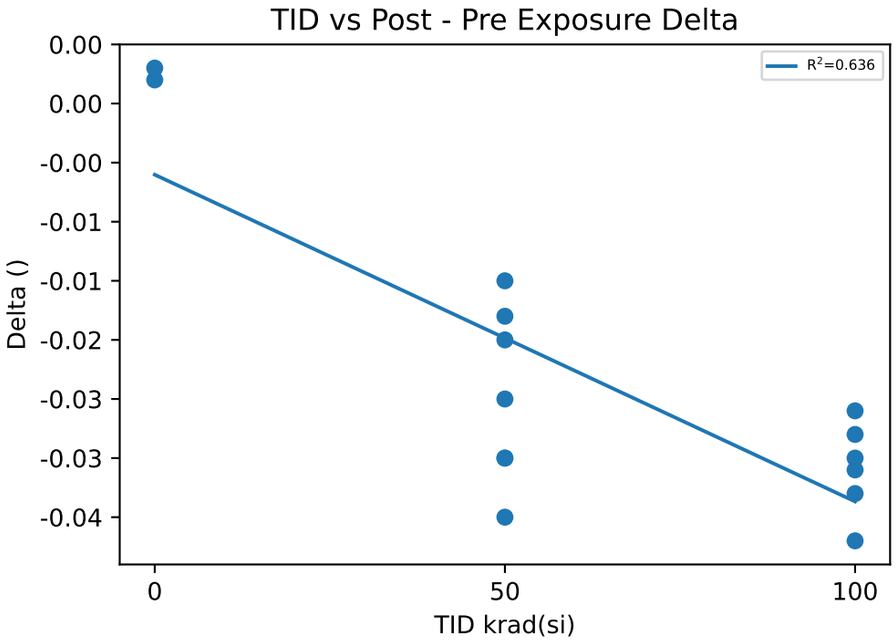
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.688	23.447	-0.241
89	50	Biased	23.829	23.869	0.04
90	50	Biased	23.71	23.494	-0.216
92	50	Biased	23.68	23.438	-0.242
93	50	Unbiased	23.268	23.342	0.074
94	50	Unbiased	23.655	23.542	-0.113
95	50	Unbiased	23.519	23.435	-0.084
96	100	Biased	23.673	23.53	-0.143
97	100	Biased	23.696	23.727	0.031
98	100	Biased	23.552	23.539	-0.013
99	100	Unbiased	24.016	24.104	0.088
100	100	Unbiased	23.642	23.575	-0.067
101	100	Unbiased	23.682	23.664	-0.018
102	0	Correlation	24.133	24.015	-0.118
103	0	Correlation	24.018	24.012	-0.006

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.018	24.075	24.133	0.081317	24.012	24.014	24.015	0.0021213	-0.118	-0.062	-0.006	0.079196
50	23.268	23.621	23.829	0.18043	23.342	23.51	23.869	0.16988	-0.242	-0.11171	0.074	0.13092
100	23.552	23.71	24.016	0.15848	23.53	23.69	24.104	0.21683	-0.143	-0.020333	0.088	0.079568

Device Test: 5.9 PROPD_RESET(tpd_RESETB4_SD/RESETB4/1.6/14/0/0/0/@PROPD_RESET)





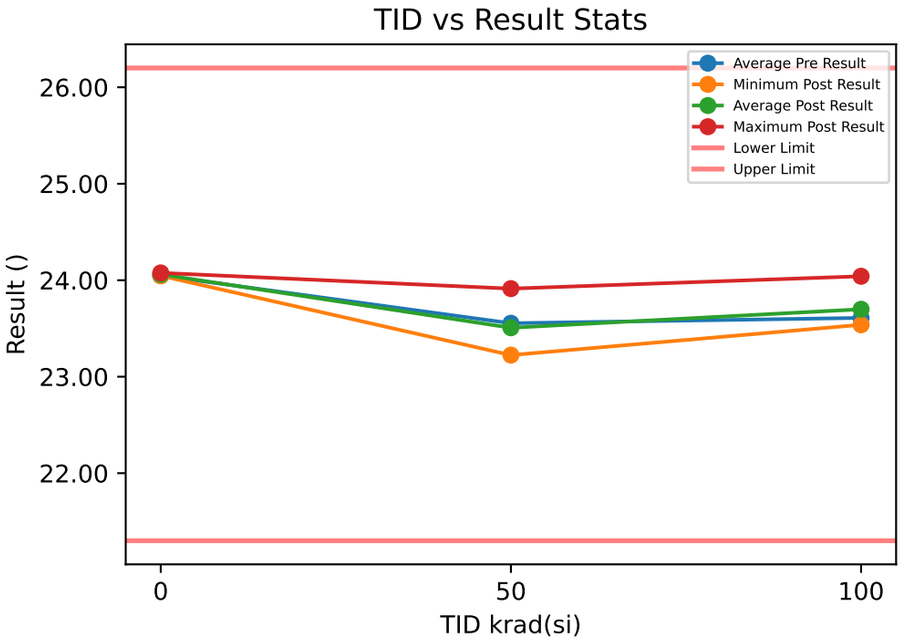
Test Results (Upper Limit = 4.3 ())

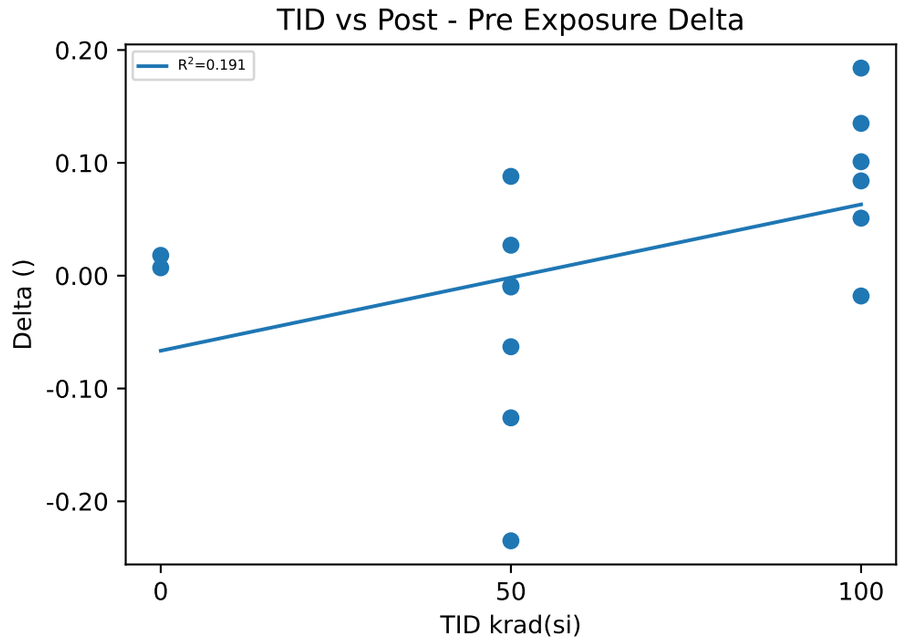
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.735	0.705	-0.03
89	50	Biased	0.724	0.704	-0.02
90	50	Biased	0.722	0.697	-0.025
92	50	Biased	0.74	0.722	-0.018
93	50	Unbiased	0.738	0.723	-0.015
94	50	Unbiased	0.727	0.692	-0.035
95	50	Unbiased	0.732	0.702	-0.03
96	100	Biased	0.713	0.683	-0.03
97	100	Biased	0.722	0.696	-0.026
98	100	Biased	0.713	0.682	-0.031
99	100	Unbiased	0.724	0.696	-0.028
100	100	Unbiased	0.74	0.703	-0.037
101	100	Unbiased	0.721	0.688	-0.033
102	0	Correlation	0.711	0.713	0.002
103	0	Correlation	0.74	0.743	0.003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.711	0.7255	0.74	0.020506	0.713	0.728	0.743	0.021213	0.002	0.0025	0.003	0.00070711
50	0.722	0.73114	0.74	0.0069864	0.692	0.70643	0.723	0.011844	-0.035	-0.024714	-0.015	0.007342
100	0.713	0.72217	0.74	0.0099079	0.682	0.69133	0.703	0.0083347	-0.037	-0.030833	-0.026	0.0038687

Device Test: 5.90 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB2_SD/RESETB2/7/14/1.18M/0/0/@DLY_TMR_1MOHM)





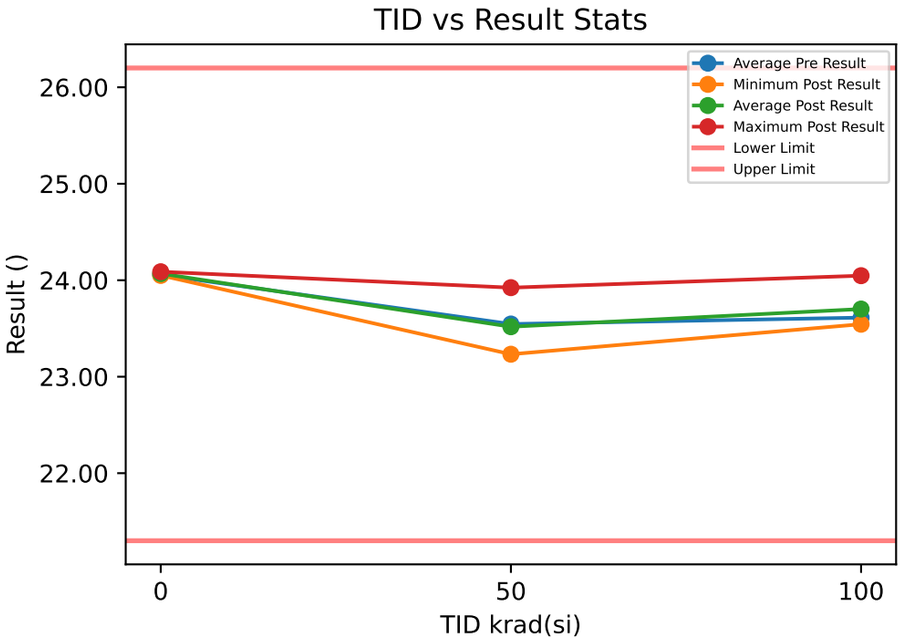
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

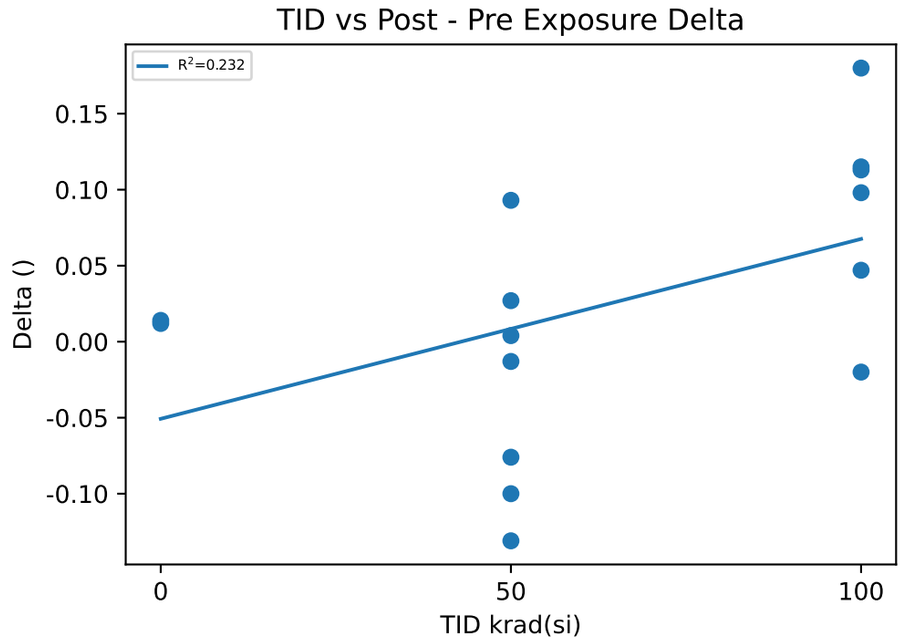
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.738	23.503	-0.235
89	50	Biased	23.825	23.913	0.088
90	50	Biased	23.565	23.502	-0.063
92	50	Biased	23.578	23.452	-0.126
93	50	Unbiased	23.197	23.224	0.027
94	50	Unbiased	23.536	23.526	-0.01
95	50	Unbiased	23.44	23.431	-0.009
96	100	Biased	23.535	23.586	0.051
97	100	Biased	23.571	23.755	0.184
98	100	Biased	23.456	23.54	0.084
99	100	Unbiased	23.94	24.041	0.101
100	100	Unbiased	23.556	23.538	-0.018
101	100	Unbiased	23.6	23.735	0.135
102	0	Correlation	24.028	24.046	0.018
103	0	Correlation	24.069	24.076	0.007

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.028	24.048	24.069	0.028991	24.046	24.061	24.076	0.021213	0.007	0.0125	0.018	0.0077782
50	23.197	23.554	23.825	0.20362	23.224	23.507	23.913	0.2058	-0.235	-0.046857	0.088	0.10674
100	23.456	23.61	23.94	0.16898	23.538	23.699	24.041	0.19254	-0.018	0.0895	0.184	0.069572

Device Test: 5.91 DLY_TMR_1MOHM(tdly_Res1p18M_RESETB4_SD/RESETB4/7/14/1.18M/0/0/@DLY_TMR_1MOHM)





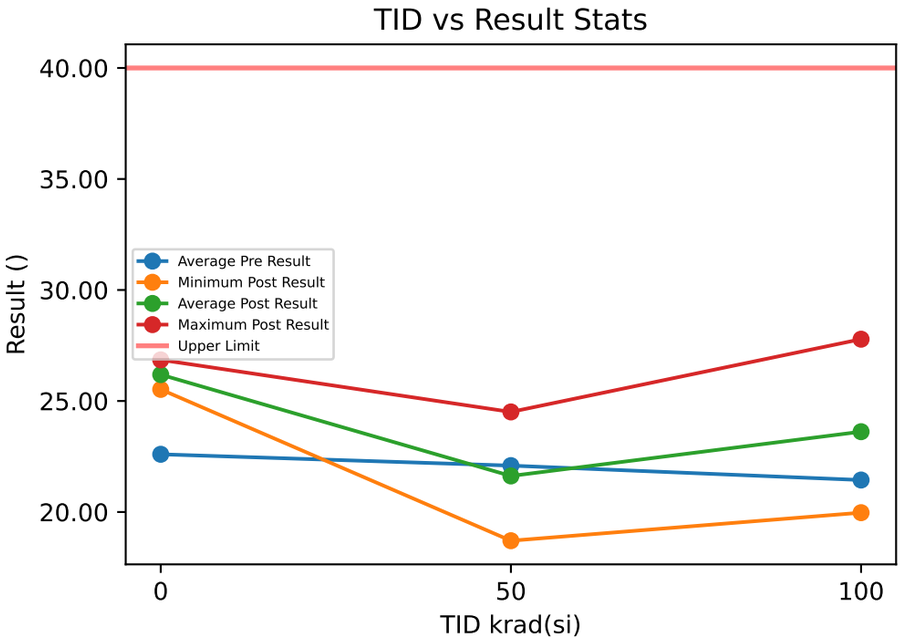
Test Results (Lower Limit = 21.3, Upper Limit = 26.2 ())

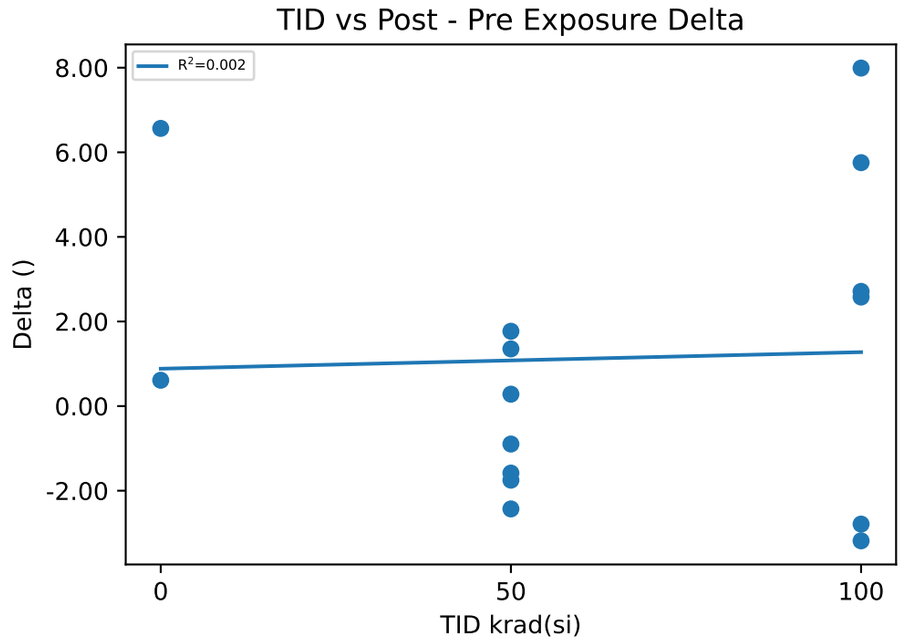
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.609	23.509	-0.1
89	50	Biased	23.83	23.923	0.093
90	50	Biased	23.596	23.52	-0.076
92	50	Biased	23.588	23.457	-0.131
93	50	Unbiased	23.206	23.233	0.027
94	50	Unbiased	23.545	23.532	-0.013
95	50	Unbiased	23.448	23.452	0.004
96	100	Biased	23.543	23.59	0.047
97	100	Biased	23.581	23.761	0.18
98	100	Biased	23.431	23.546	0.115
99	100	Unbiased	23.949	24.047	0.098
100	100	Unbiased	23.564	23.544	-0.02
101	100	Unbiased	23.607	23.72	0.113
102	0	Correlation	24.036	24.05	0.014
103	0	Correlation	24.076	24.088	0.012

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.036	24.056	24.076	0.028284	24.05	24.069	24.088	0.02687	0.012	0.013	0.014	0.0014142
50	23.206	23.546	23.83	0.1889	23.233	23.518	23.923	0.20559	-0.131	-0.028	0.093	0.078541
100	23.431	23.613	23.949	0.17572	23.544	23.701	24.047	0.19218	-0.02	0.088833	0.18	0.068204

Device Test: 5.92 PROPD_WDO_0P5(tpd_WDI_SU/WDOB/1.6/3/0/0/0/@PROPD_WDO_0P5)





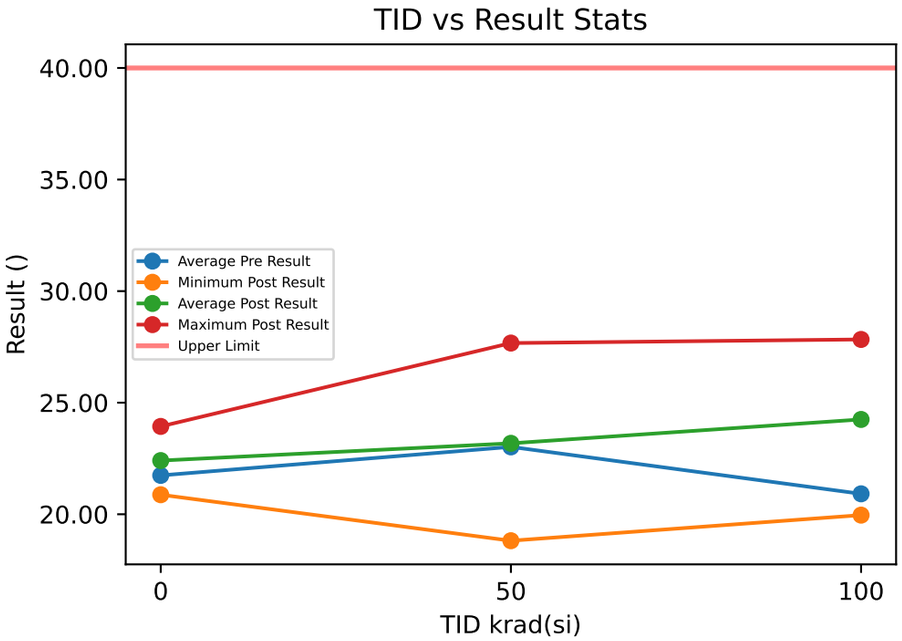
Test Results (Upper Limit = 40.0 ())

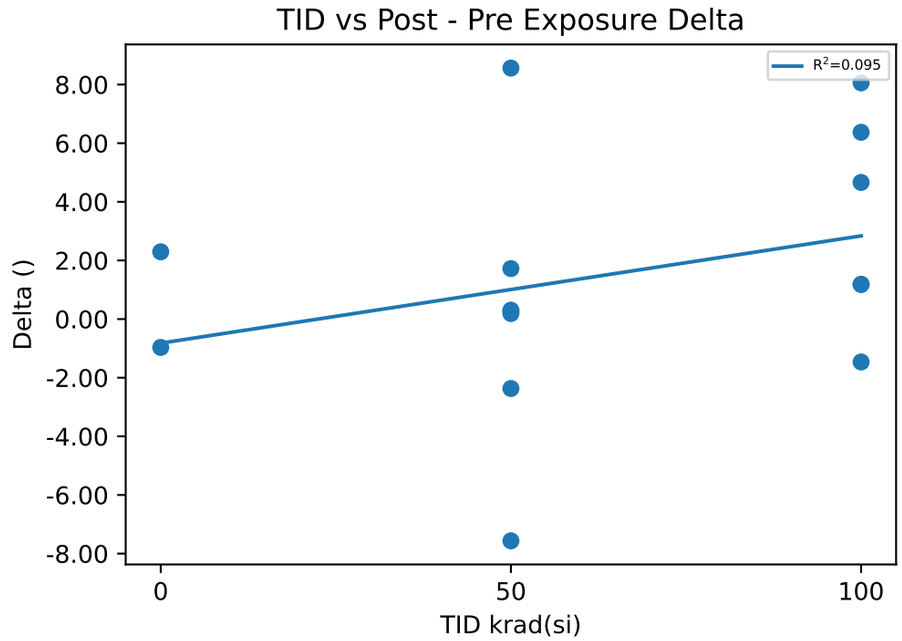
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	22.722	21.825	-0.897
89	50	Biased	25.434	23.683	-1.751
90	50	Biased	20.291	18.707	-1.584
92	50	Biased	19.402	20.754	1.352
93	50	Unbiased	20.324	20.606	0.282
94	50	Unbiased	19.517	21.286	1.769
95	50	Unbiased	26.939	24.508	-2.431
96	100	Biased	23.155	19.97	-3.185
97	100	Biased	20.016	22.728	2.712
98	100	Biased	19.928	22.506	2.578
99	100	Unbiased	25.689	22.899	-2.79
100	100	Unbiased	19.793	27.784	7.991
101	100	Unbiased	20.063	25.818	5.755
102	0	Correlation	24.912	25.523	0.611
103	0	Correlation	20.288	26.853	6.565

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.288	22.6	24.912	3.2697	25.523	26.188	26.853	0.94045	0.611	3.588	6.565	4.2101
50	19.402	22.09	26.939	3.0358	18.707	21.624	24.508	1.9585	-2.431	-0.46571	1.769	1.6232
100	19.793	21.441	25.689	2.4461	19.97	23.618	27.784	2.7586	-3.185	2.1768	7.991	4.4827

Device Test: 5.93 PROPD_WDO_0P5(tpd_WDI_SU/WDOB/1.6/14/0/0/0/@PROPD_WDO_0P5)





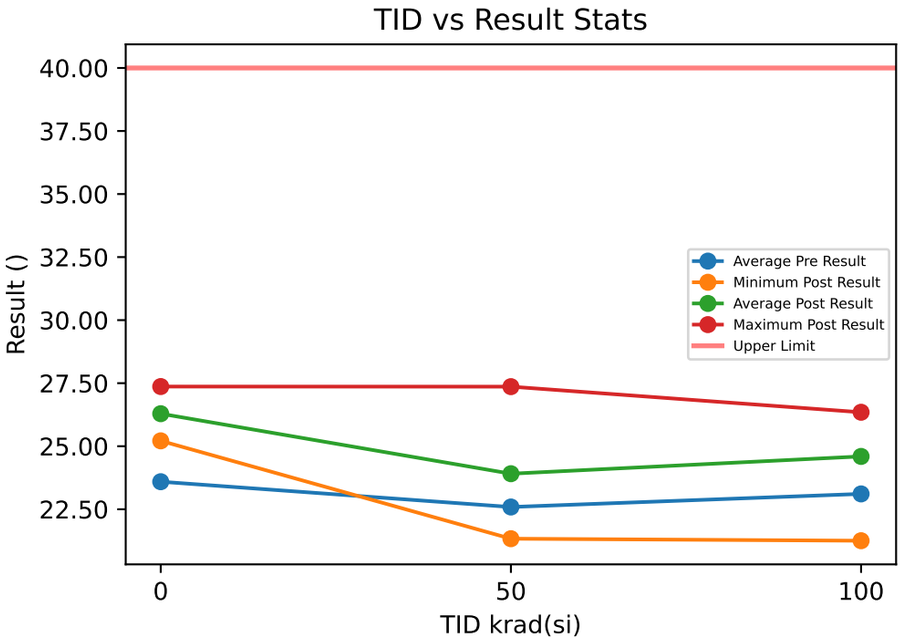
Test Results (Upper Limit = 40.0 ())

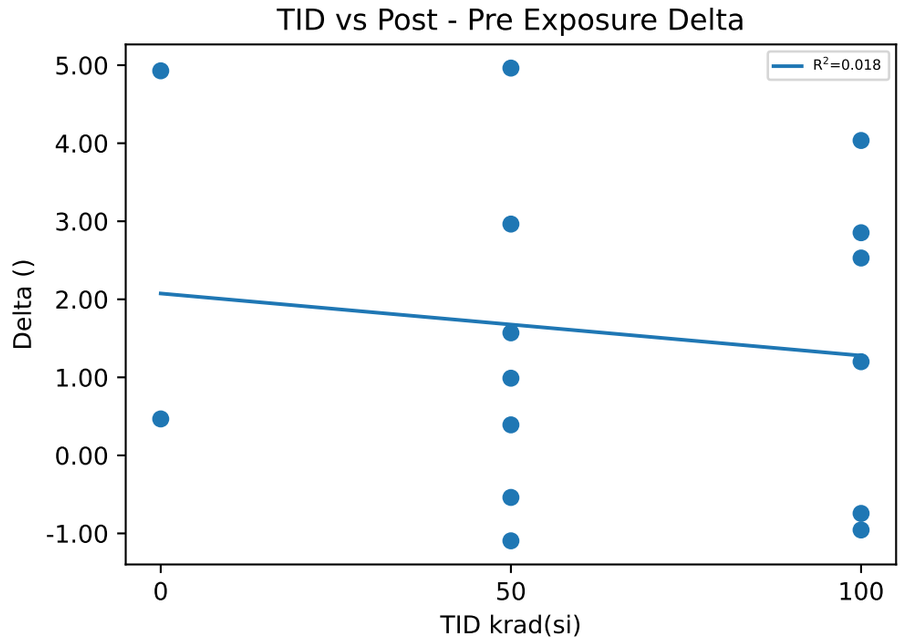
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.32	23.593	0.273
89	50	Biased	19.276	20.998	1.722
90	50	Biased	26.378	18.814	-7.564
92	50	Biased	19.11	27.672	8.562
93	50	Unbiased	19.989	20.178	0.189
94	50	Unbiased	26.385	26.689	0.304
95	50	Unbiased	26.674	24.306	-2.368
96	100	Biased	18.779	19.961	1.182
97	100	Biased	20.646	21.831	1.185
98	100	Biased	25.851	24.388	-1.463
99	100	Unbiased	19.162	23.824	4.662
100	100	Unbiased	19.596	27.654	8.058
101	100	Unbiased	21.462	27.834	6.372
102	0	Correlation	24.903	23.936	-0.967
103	0	Correlation	18.58	20.875	2.295

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.58	21.741	24.903	4.471	20.875	22.405	23.936	2.1645	-0.967	0.664	2.295	2.3066
50	19.11	23.019	26.674	3.5245	18.814	23.179	27.672	3.3358	-7.564	0.15971	8.562	4.8152
100	18.779	20.916	25.851	2.6119	19.961	24.249	27.834	3.1267	-1.463	3.3327	8.058	3.6213

Device Test: 5.94 PROPD_WDO_0P5(tpd_WDI_SU/WDOB/7/3/0/0/0/@PROPD_WDO_0P5)





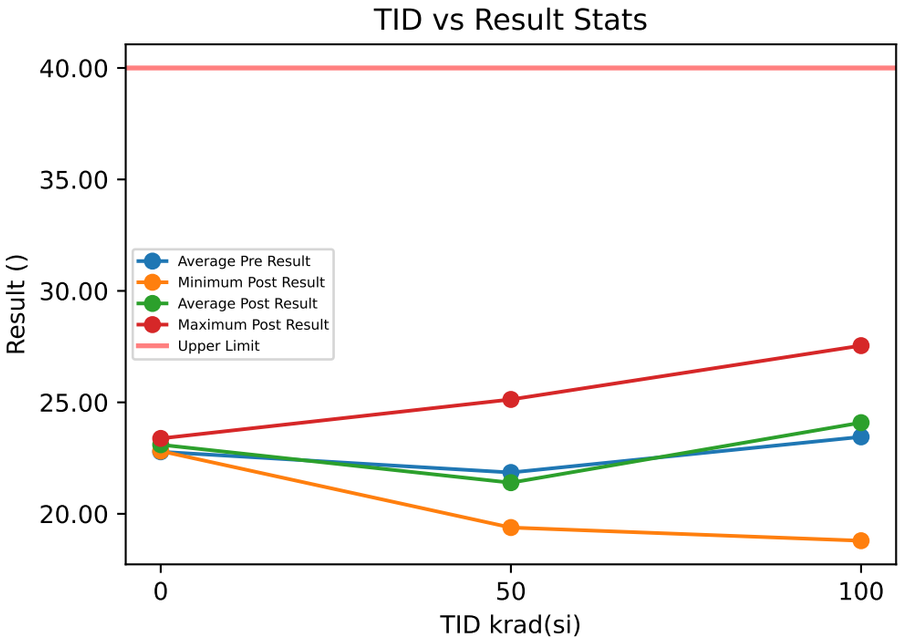
Test Results (Upper Limit = 40.0 ())

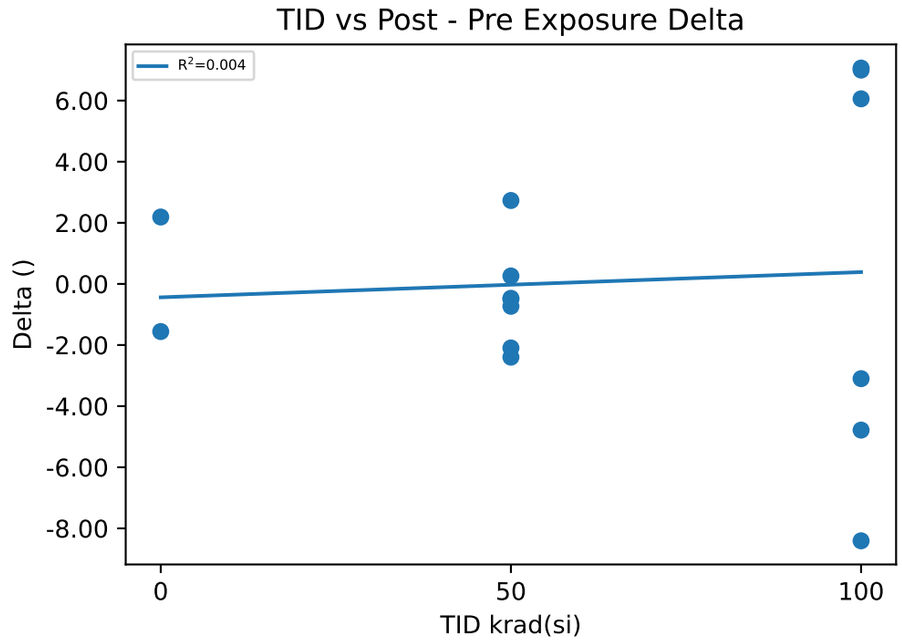
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	22.399	27.362	4.963
89	50	Biased	22.57	25.534	2.964
90	50	Biased	21.231	22.22	0.989
92	50	Biased	21.373	22.943	1.57
93	50	Unbiased	21.979	21.44	-0.539
94	50	Unbiased	20.941	21.332	0.391
95	50	Unbiased	27.631	26.536	-1.095
96	100	Biased	23.351	26.204	2.853
97	100	Biased	23.818	26.347	2.529
98	100	Biased	22.208	21.252	-0.956
99	100	Unbiased	20.161	24.196	4.035
100	100	Unbiased	22.336	23.536	1.2
101	100	Unbiased	26.777	26.033	-0.744
102	0	Correlation	24.746	25.213	0.467
103	0	Correlation	22.438	27.366	4.928

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.438	23.592	24.746	1.632	25.213	26.29	27.366	1.5224	0.467	2.6975	4.928	3.1544
50	20.941	22.589	27.631	2.3047	21.332	23.91	27.362	2.5162	-1.095	1.3204	4.963	2.0935
100	20.161	23.109	26.777	2.1962	21.252	24.595	26.347	2.0091	-0.956	1.4862	4.035	2.0235

Device Test: 5.95 PROPD_WDO_0P5(tpd_WDI_SU/WDOB/7/14/0/0/0/@PROPD_WDO_0P5)





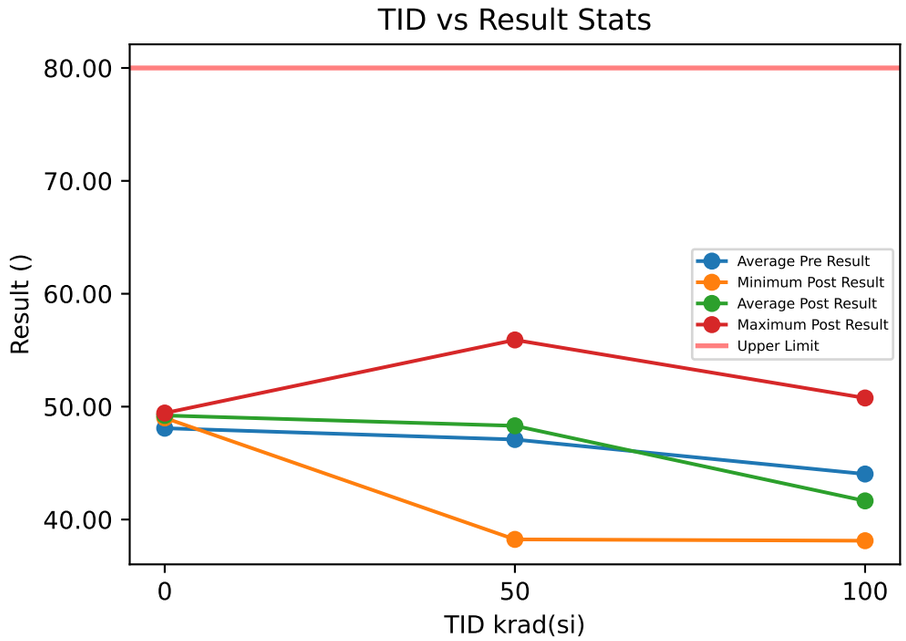
Test Results (Upper Limit = 40.0 ())

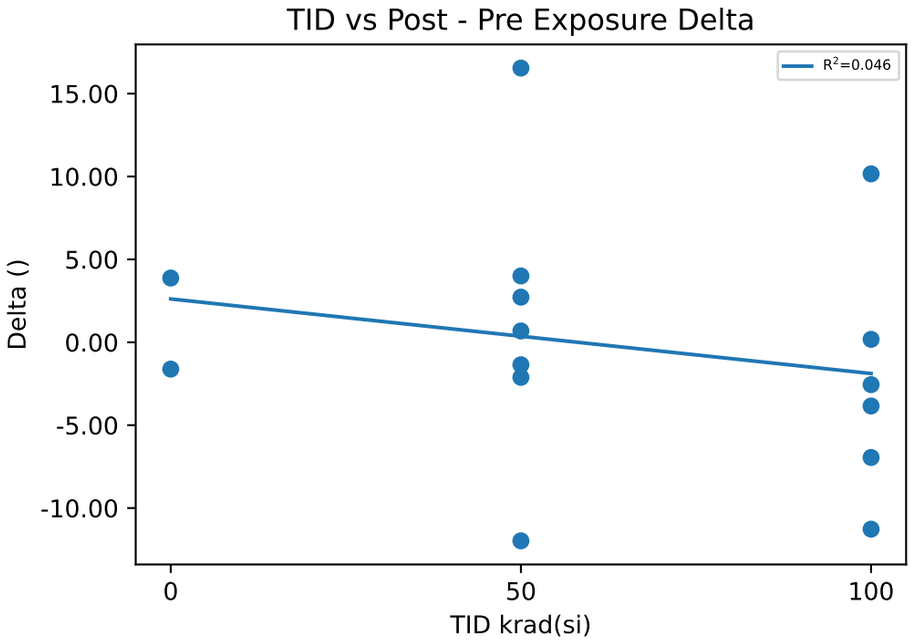
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.734	23.002	-0.732
89	50	Biased	18.837	21.567	2.73
90	50	Biased	20.386	19.891	-0.495
92	50	Biased	21.43	20.959	-0.471
93	50	Unbiased	21.781	19.384	-2.397
94	50	Unbiased	19.579	19.839	0.26
95	50	Unbiased	27.226	25.13	-2.096
96	100	Biased	19.757	26.821	7.064
97	100	Biased	26.871	22.087	-4.784
98	100	Biased	19.364	26.362	6.998
99	100	Unbiased	26.028	22.927	-3.101
100	100	Unbiased	27.201	18.793	-8.408
101	100	Unbiased	21.486	27.544	6.058
102	0	Correlation	24.373	22.814	-1.559
103	0	Correlation	21.193	23.382	2.189

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.193	22.783	24.373	2.2486	22.814	23.098	23.382	0.40164	-1.559	0.315	2.189	2.6502
50	18.837	21.853	27.226	2.8581	19.384	21.396	25.13	2.0607	-2.397	-0.45729	2.73	1.693
100	19.364	23.451	27.201	3.6499	18.793	24.089	27.544	3.4051	-8.408	0.63783	7.064	6.875

Device Test: 5.96 PROPD_WDO_1(tpd_WDI_SU/WDOB/1.6/3/0/0/0/@PROPD_WDO_1)





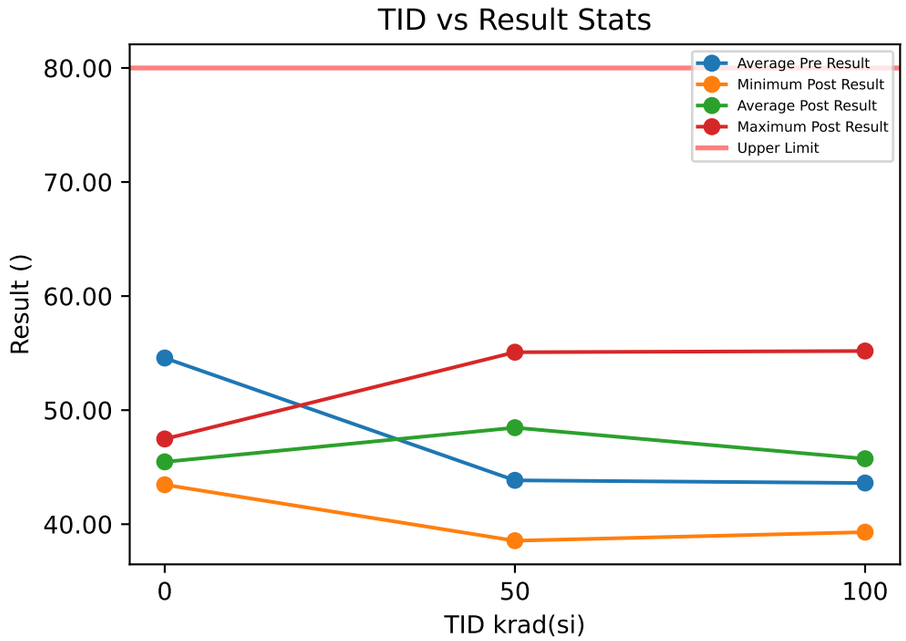
Test Results (Upper Limit = 80.0 ())

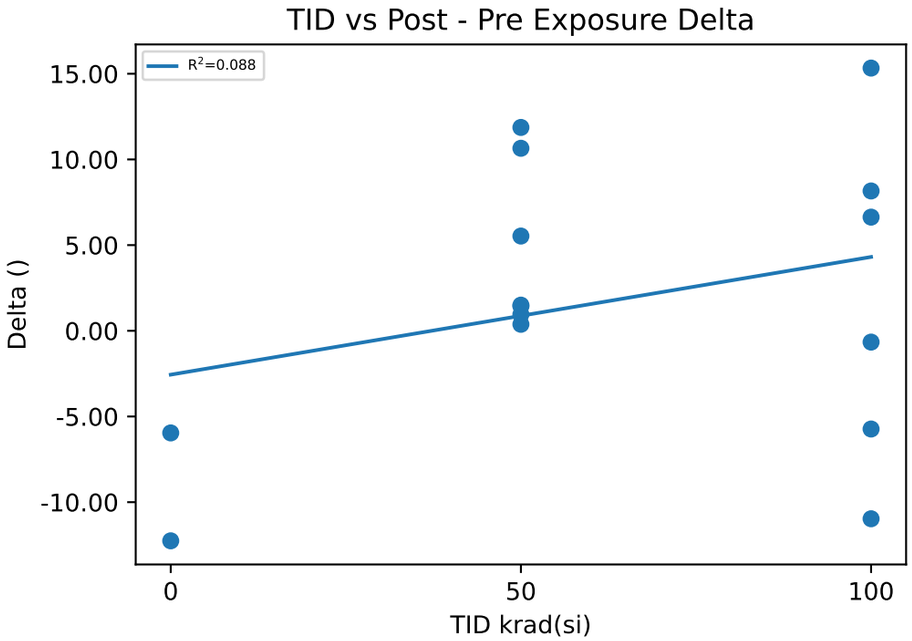
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	40.827	39.471	-1.356
89	50	Biased	50.898	53.62	2.722
90	50	Biased	39.367	55.908	16.541
92	50	Biased	50.114	54.115	4.001
93	50	Unbiased	50.216	38.24	-11.976
94	50	Unbiased	48.802	46.687	-2.115
95	50	Unbiased	49.395	50.078	0.683
96	100	Biased	40.606	50.766	10.16
97	100	Biased	41.161	38.607	-2.554
98	100	Biased	45.072	38.123	-6.949
99	100	Unbiased	42.746	38.903	-3.843
100	100	Unbiased	53.495	42.222	-11.273
101	100	Unbiased	41.11	41.287	0.177
102	0	Correlation	51.051	49.433	-1.618
103	0	Correlation	45.126	49.002	3.876

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.126	48.088	51.051	4.1896	49.002	49.218	49.433	0.30476	-1.618	1.129	3.876	3.8848
50	39.367	47.088	50.898	4.8396	38.24	48.303	55.908	7.1288	-11.976	1.2143	16.541	8.5333
100	40.606	44.032	53.495	4.9153	38.123	41.651	50.766	4.7499	-11.273	-2.3803	10.16	7.2928

Device Test: 5.97 PROPD_WDO_1(tpd_WDI_SU/WDOB/1.6/14/0/0/0/@PROPD_WDO_1)





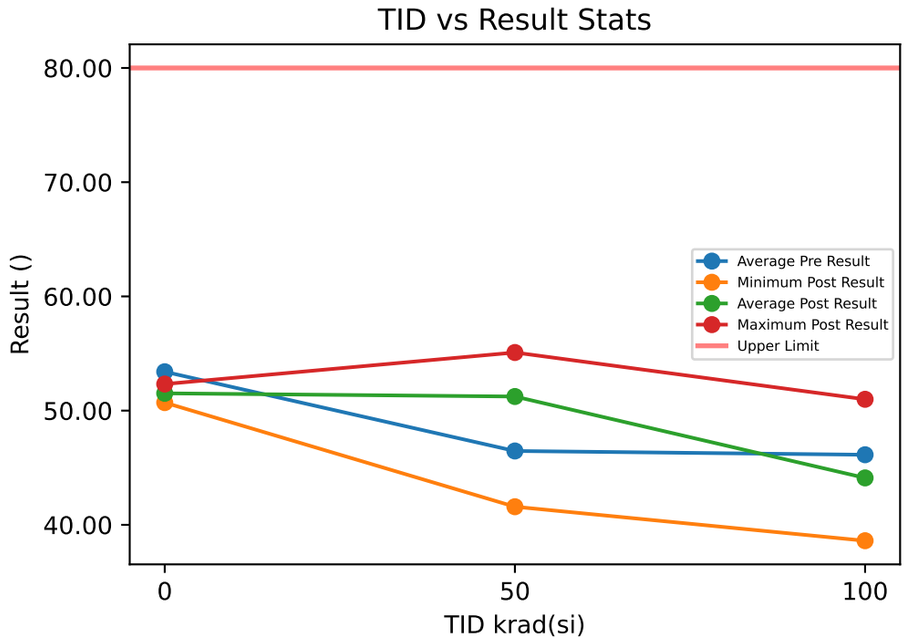
Test Results (Upper Limit = 80.0 ())

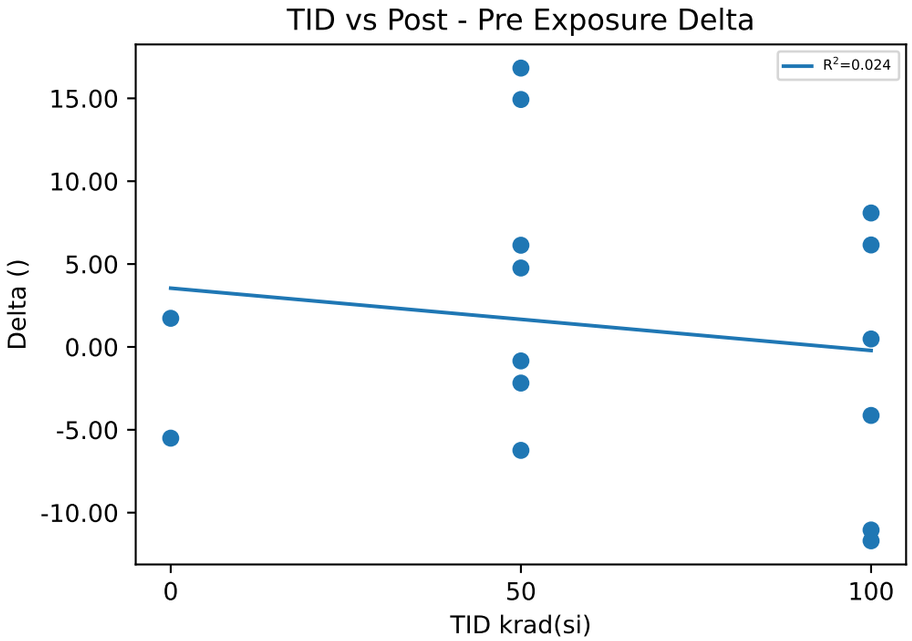
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	39.532	39.912	0.38
89	50	Biased	51.849	53.287	1.438
90	50	Biased	37.595	38.552	0.957
92	50	Biased	42.361	53.012	10.651
93	50	Unbiased	49.55	55.079	5.529
94	50	Unbiased	45.594	47.092	1.498
95	50	Unbiased	40.437	52.304	11.867
96	100	Biased	42.324	50.484	8.16
97	100	Biased	40.314	39.655	-0.659
98	100	Biased	39.853	55.184	15.331
99	100	Unbiased	45.033	39.302	-5.731
100	100	Unbiased	52.718	41.75	-10.968
101	100	Unbiased	41.43	48.063	6.633
102	0	Correlation	53.432	47.473	-5.959
103	0	Correlation	55.714	43.459	-12.255

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	53.432	54.573	55.714	1.6136	43.459	45.466	47.473	2.8383	-12.255	-9.107	-5.959	4.4519
50	37.595	43.845	51.849	5.3409	38.552	48.463	55.079	6.7788	0.38	4.6171	11.867	4.8474
100	39.853	43.612	52.718	4.8242	39.302	45.74	55.184	6.5036	-10.968	2.1277	15.331	9.7163

Device Test: 5.98 PROPD_WDO_1(tpd_WDI_SU/WDOB/7/3/0/0/0/@PROPD_WDO_1)





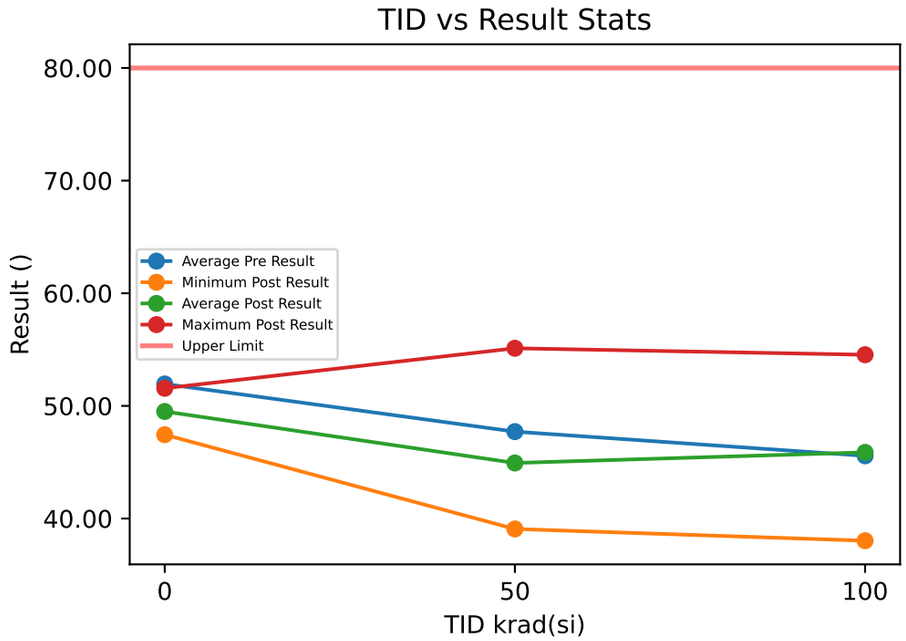
Test Results (Upper Limit = 80.0 ())

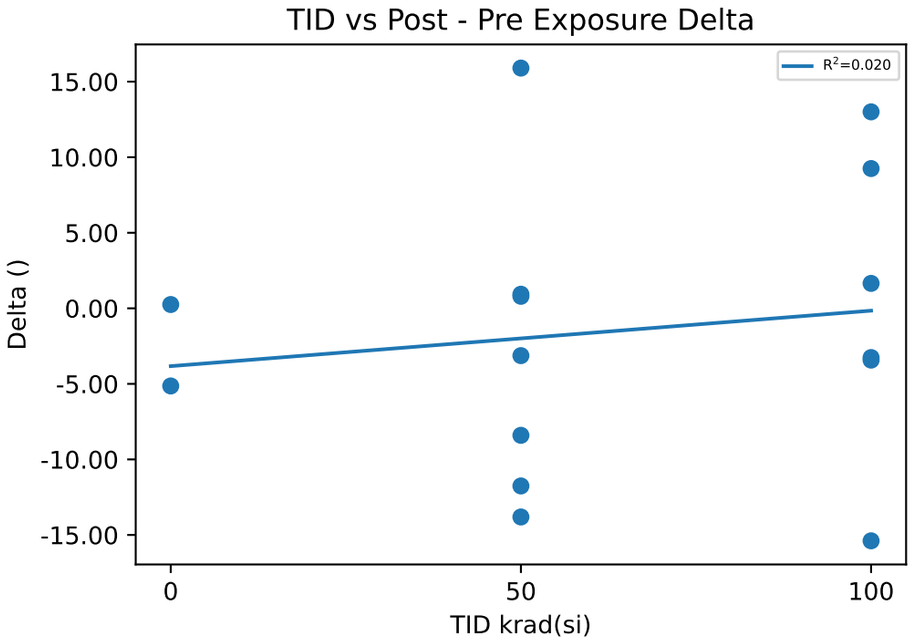
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	38.158	54.984	16.826
89	50	Biased	50.325	55.087	4.762
90	50	Biased	40.052	54.981	14.929
92	50	Biased	43.766	41.585	-2.181
93	50	Unbiased	48.743	54.879	6.136
94	50	Unbiased	47.938	47.093	-0.845
95	50	Unbiased	56.277	50.035	-6.242
96	100	Biased	42.91	50.992	8.082
97	100	Biased	42.536	43.016	0.48
98	100	Biased	42.743	38.609	-4.134
99	100	Unbiased	51.312	39.612	-11.7
100	100	Unbiased	53.679	42.633	-11.046
101	100	Unbiased	43.636	49.788	6.152
102	0	Correlation	50.6	52.327	1.727
103	0	Correlation	56.207	50.702	-5.505

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.6	53.404	56.207	3.9647	50.702	51.514	52.327	1.149	-5.505	-1.889	1.727	5.1138
50	38.158	46.466	56.277	6.271	41.585	51.235	55.087	5.2903	-6.242	4.7693	16.826	8.6749
100	42.536	46.136	53.679	4.9963	38.609	44.108	50.992	5.1667	-11.7	-2.0277	8.082	8.4228

Device Test: 5.99 PROPD_WDO_1(tpd_WDI_SU/WDOB/7/14/0/0/0/@PROPD_WDO_1)





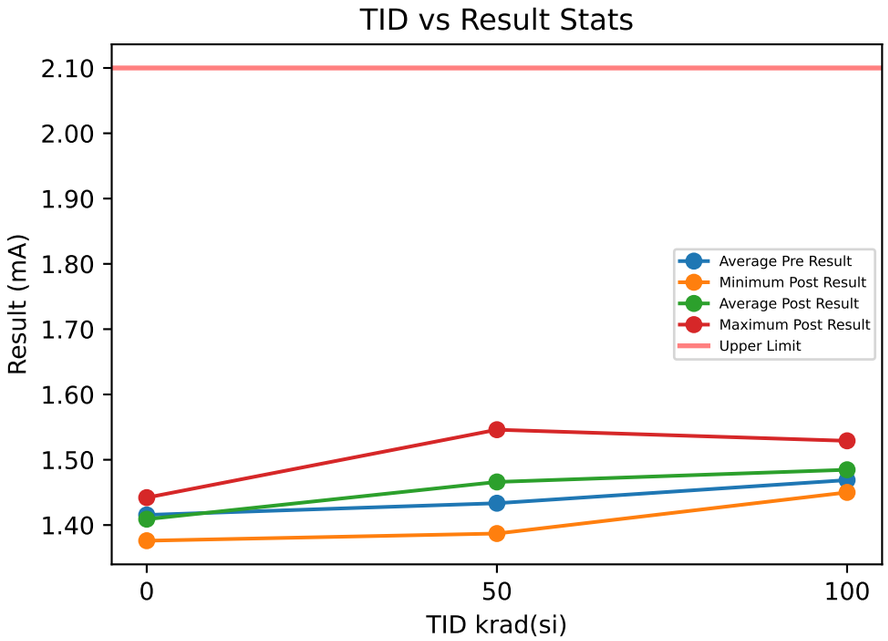
Test Results (Upper Limit = 80.0 ())

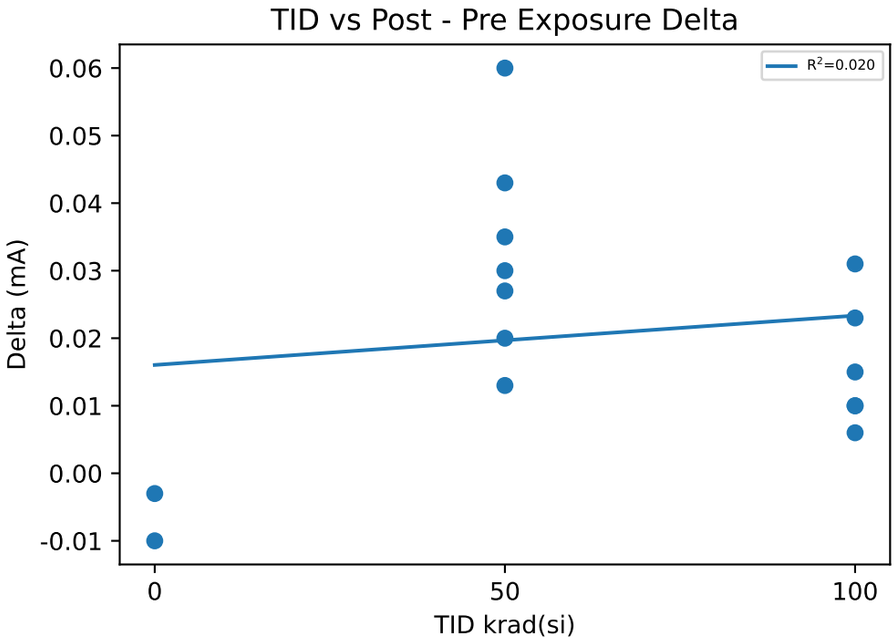
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	39.308	40.103	0.795
89	50	Biased	51.338	52.271	0.933
90	50	Biased	39.217	55.117	15.9
92	50	Biased	53.546	39.736	-13.81
93	50	Unbiased	47.481	39.075	-8.406
94	50	Unbiased	48.576	45.445	-3.131
95	50	Unbiased	54.549	42.792	-11.757
96	100	Biased	53.688	50.26	-3.428
97	100	Biased	41.539	54.542	13.003
98	100	Biased	41.291	38.032	-3.259
99	100	Unbiased	45.006	46.656	1.65
100	100	Unbiased	53.758	38.37	-15.388
101	100	Unbiased	38.139	47.39	9.251
102	0	Correlation	51.314	51.565	0.251
103	0	Correlation	52.583	47.444	-5.139

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.314	51.948	52.583	0.89732	47.444	49.505	51.565	2.914	-5.139	-2.444	0.251	3.8113
50	39.217	47.716	54.549	6.2918	39.075	44.934	55.117	6.4169	-13.81	-2.7823	15.9	10.079
100	38.139	45.57	53.758	6.679	38.032	45.875	54.542	6.5588	-15.388	0.30483	13.003	10.159

Device Test: 6.0 ISD(ISD/IN//3/0/0/0/@ISD)





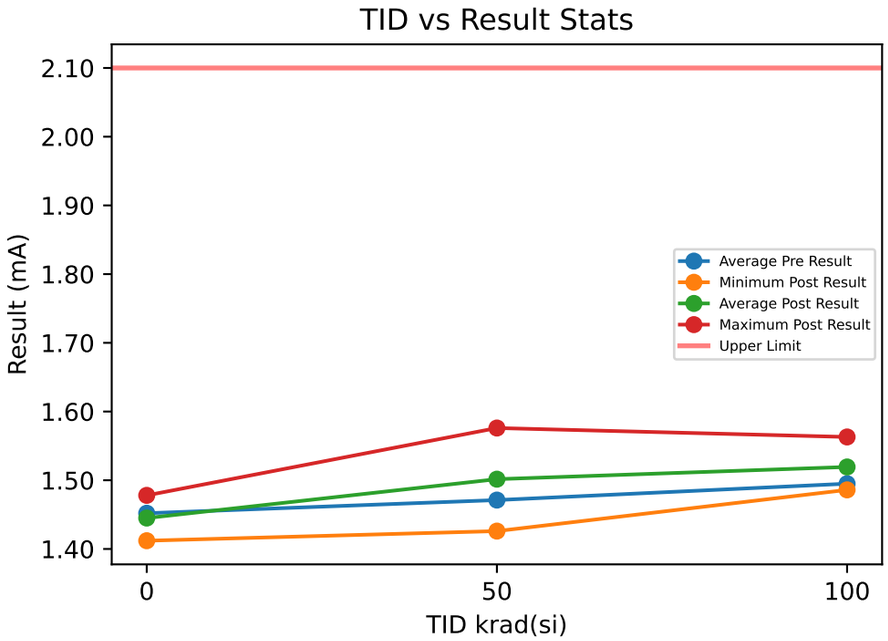
Test Results (Upper Limit = 2.1 (mA))

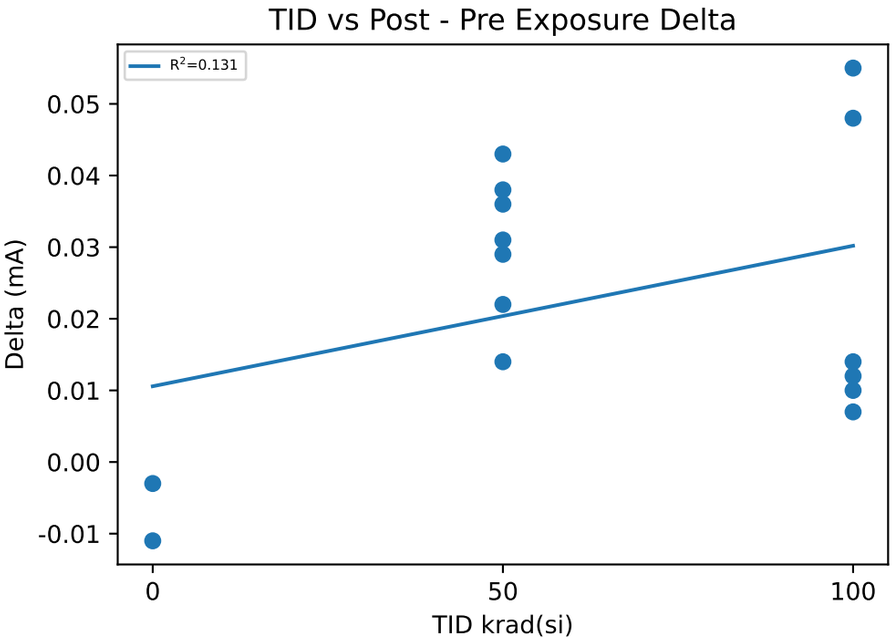
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.421	1.456	0.035
89	50	Biased	1.484	1.514	0.03
90	50	Biased	1.503	1.546	0.043
92	50	Biased	1.452	1.465	0.013
93	50	Unbiased	1.411	1.431	0.02
94	50	Unbiased	1.403	1.463	0.06
95	50	Unbiased	1.36	1.387	0.027
96	100	Biased	1.519	1.529	0.01
97	100	Biased	1.419	1.45	0.031
98	100	Biased	1.471	1.477	0.006
99	100	Unbiased	1.481	1.496	0.015
100	100	Unbiased	1.453	1.463	0.01
101	100	Unbiased	1.47	1.493	0.023
102	0	Correlation	1.445	1.442	-0.003
103	0	Correlation	1.386	1.376	-0.01

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.386	1.4155	1.445	0.041719	1.376	1.409	1.442	0.046669	-0.01	-0.0065	-0.003	0.0049497
50	1.36	1.4334	1.503	0.049527	1.387	1.466	1.546	0.05209	0.013	0.032571	0.06	0.015523
100	1.419	1.4688	1.519	0.032878	1.45	1.4847	1.529	0.027905	0.006	0.015833	0.031	0.0094534

Device Test: 6.1 ISD(ISD/IN//14/0/0/0/@ISD)





Test Results (Upper Limit = 2.1 (mA))

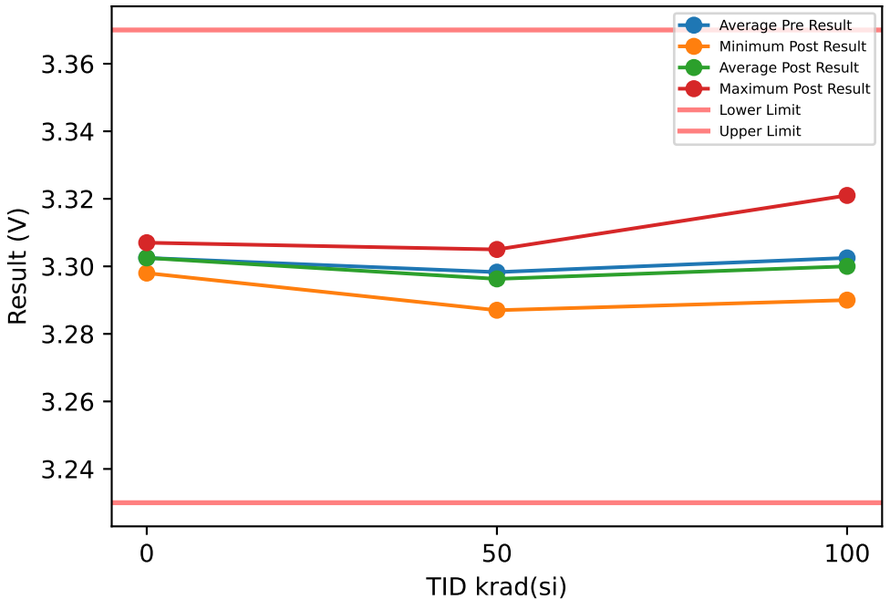
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.455	1.491	0.036
89	50	Biased	1.518	1.549	0.031
90	50	Biased	1.533	1.576	0.043
92	50	Biased	1.489	1.503	0.014
93	50	Unbiased	1.446	1.468	0.022
94	50	Unbiased	1.46	1.498	0.038
95	50	Unbiased	1.397	1.426	0.029
96	100	Biased	1.551	1.563	0.012
97	100	Biased	1.431	1.486	0.055
98	100	Biased	1.51	1.517	0.007
99	100	Unbiased	1.513	1.527	0.014
100	100	Unbiased	1.487	1.497	0.01
101	100	Unbiased	1.478	1.526	0.048
102	0	Correlation	1.481	1.478	-0.003
103	0	Correlation	1.423	1.412	-0.011

Test Statistics (mA)

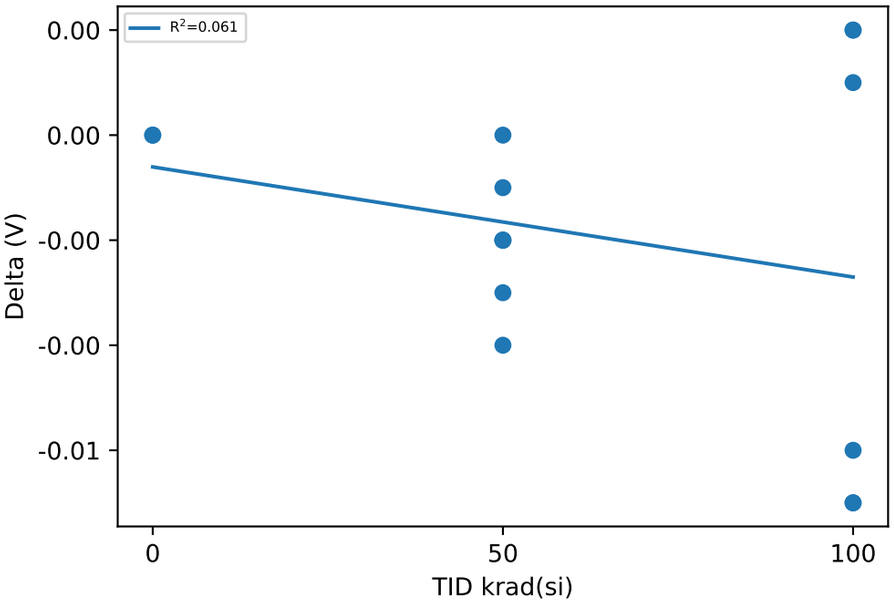
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.423	1.452	1.481	0.041012	1.412	1.445	1.478	0.046669	-0.011	-0.007	-0.003	0.0056569
50	1.397	1.4711	1.533	0.046287	1.426	1.5016	1.576	0.049588	0.014	0.030429	0.043	0.0099139
100	1.431	1.495	1.551	0.040334	1.486	1.5193	1.563	0.026927	0.007	0.024333	0.055	0.021285

Device Test: 6.10 VLDO_REG(VLDO/VLDO//14/0/0/0/@VLDO_REG)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



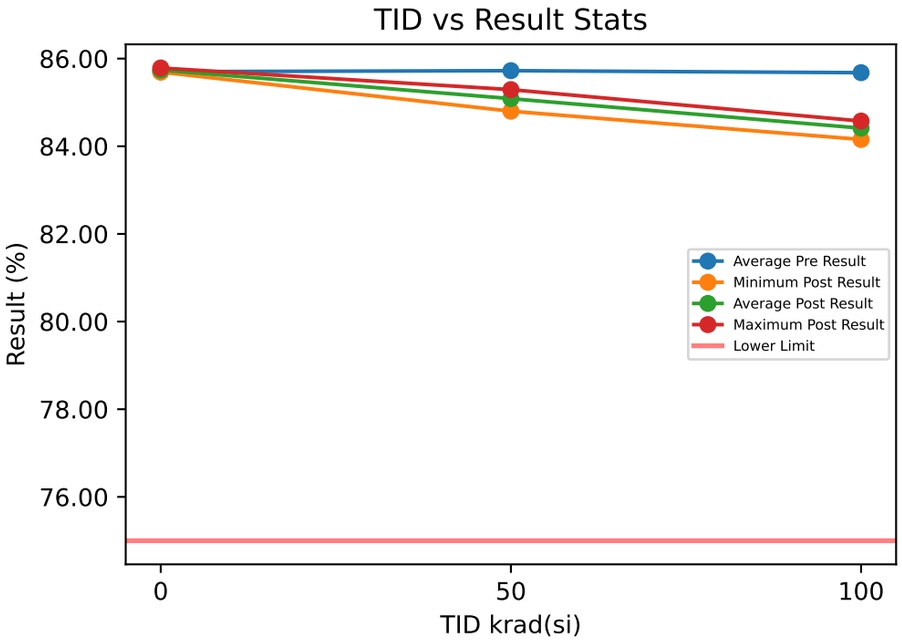
Test Results (Lower Limit = 3.23, Upper Limit = 3.37 (V))

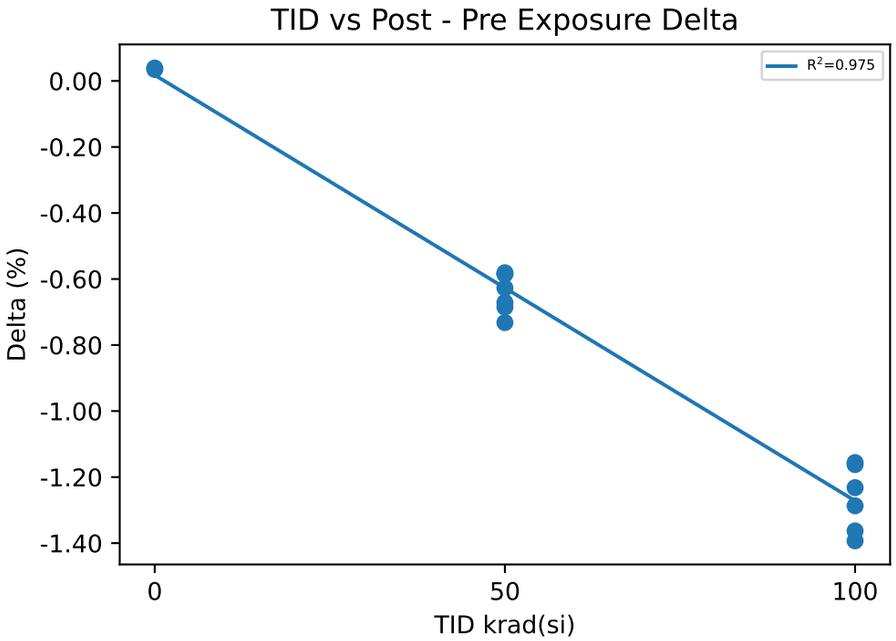
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	3.292	3.292	0
89	50	Biased	3.305	3.303	-0.002
90	50	Biased	3.289	3.287	-0.002
92	50	Biased	3.306	3.304	-0.002
93	50	Unbiased	3.309	3.305	-0.004
94	50	Unbiased	3.291	3.29	-0.001
95	50	Unbiased	3.296	3.293	-0.003
96	100	Biased	3.304	3.297	-0.007
97	100	Biased	3.303	3.297	-0.006
98	100	Biased	3.319	3.321	0.002
99	100	Unbiased	3.298	3.299	0.001
100	100	Unbiased	3.294	3.296	0.002
101	100	Unbiased	3.297	3.29	-0.007
102	0	Correlation	3.307	3.307	0
103	0	Correlation	3.298	3.298	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.298	3.3025	3.307	0.006364	3.298	3.3025	3.307	0.006364	0	0	0	0
50	3.289	3.2983	3.309	0.0081999	3.287	3.2963	3.305	0.0074769	-0.004	-0.002	0	0.001291
100	3.294	3.3025	3.319	0.0089163	3.29	3.3	3.321	0.010733	-0.007	-0.0025	0.002	0.0045935

Device Test: 6.100 VOH_PWRGD_10MA(VOH_10mA_PWRGD/PWRGD/1.6/14/0/0/10/@VOH_PWRGD_10MA)





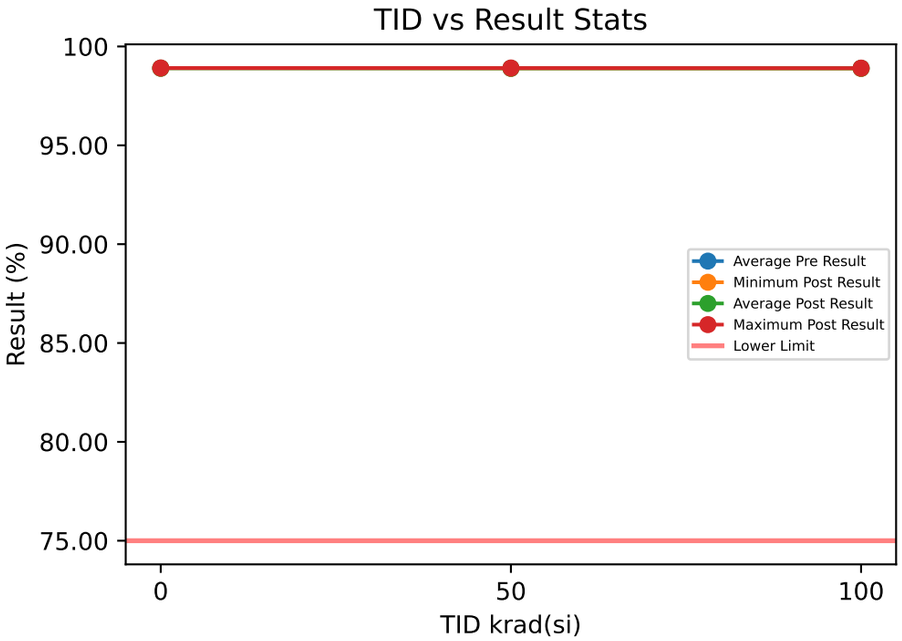
Test Results (Lower Limit = 75.0 (%))

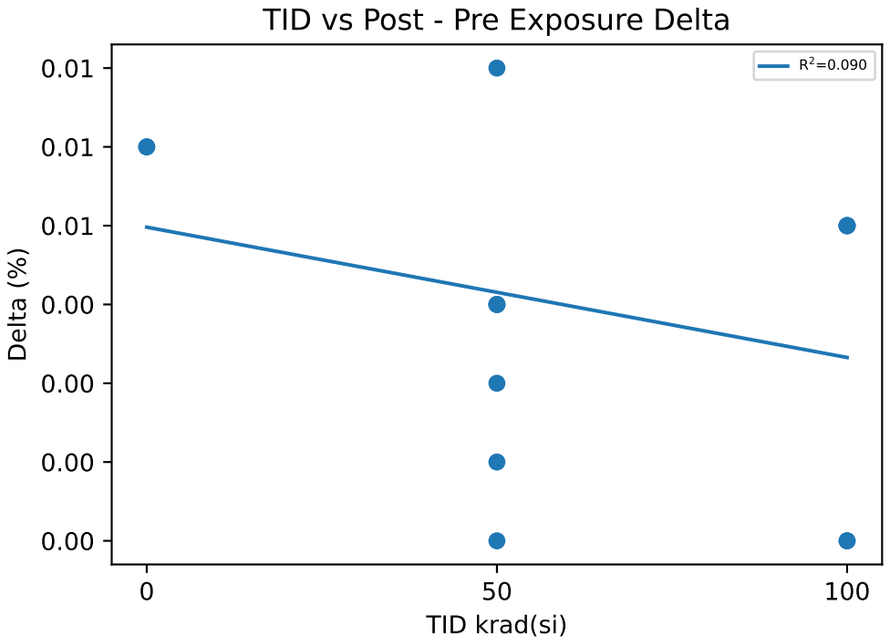
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	85.831	85.247	-0.584
89	50	Biased	85.884	85.213	-0.671
90	50	Biased	85.75	85.065	-0.685
92	50	Biased	85.532	84.8	-0.732
93	50	Unbiased	85.575	84.948	-0.627
94	50	Unbiased	85.873	85.292	-0.581
95	50	Unbiased	85.626	85.041	-0.585
96	100	Biased	85.776	84.489	-1.287
97	100	Biased	85.548	84.155	-1.393
98	100	Biased	85.712	84.349	-1.363
99	100	Unbiased	85.737	84.575	-1.162
100	100	Unbiased	85.67	84.514	-1.156
101	100	Unbiased	85.63	84.398	-1.232
102	0	Correlation	85.747	85.786	0.039
103	0	Correlation	85.656	85.691	0.035

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	85.656	85.702	85.747	0.064347	85.691	85.739	85.786	0.067175	0.035	0.037	0.039	0.0028284
50	85.532	85.724	85.884	0.1464	84.8	85.087	85.292	0.17691	-0.732	-0.63786	-0.581	0.059482
100	85.548	85.679	85.776	0.081859	84.155	84.413	84.575	0.1504	-1.393	-1.2655	-1.156	0.10005

Device Test: 6.101 VOH_RESET_10MA(VOH_10mA_RESETB1/RESETB1/7/3/0/0/10/@VOH_RESET_10MA)





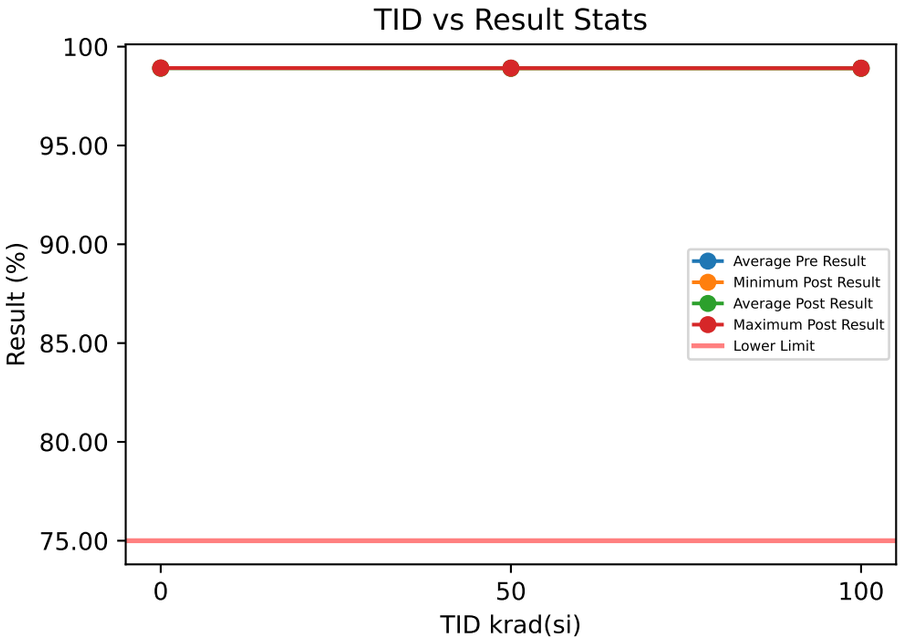
Test Results (Lower Limit = 75.0 (%))

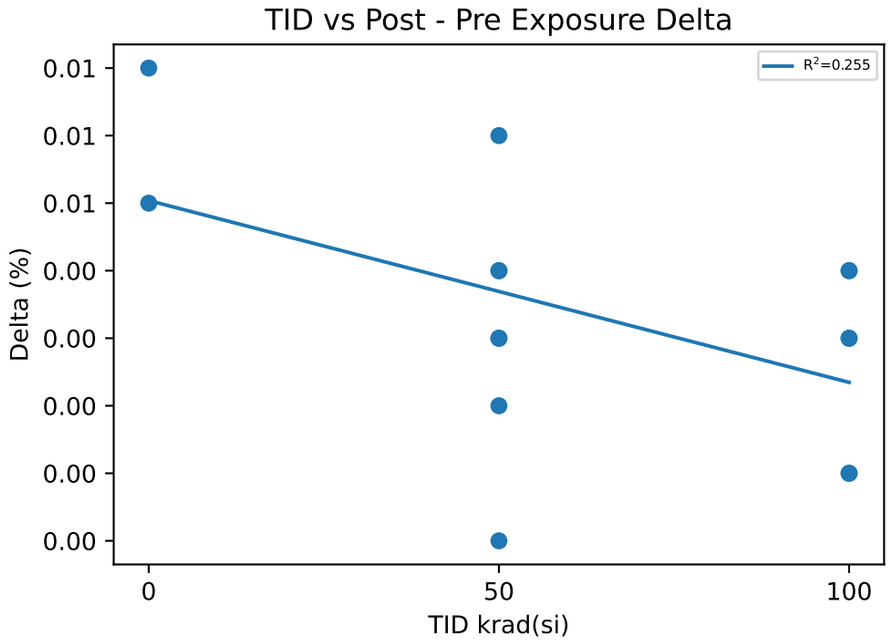
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	98.892	98.899	0.007
89	50	Biased	98.894	98.898	0.004
90	50	Biased	98.897	98.901	0.004
92	50	Biased	98.889	98.89	0.001
93	50	Unbiased	98.897	98.899	0.002
94	50	Unbiased	98.893	98.896	0.003
95	50	Unbiased	98.906	98.91	0.004
96	100	Biased	98.885	98.886	0.001
97	100	Biased	98.899	98.904	0.005
98	100	Biased	98.9	98.905	0.005
99	100	Unbiased	98.897	98.902	0.005
100	100	Unbiased	98.892	98.897	0.005
101	100	Unbiased	98.897	98.898	0.001
102	0	Correlation	98.906	98.912	0.006
103	0	Correlation	98.891	98.897	0.006

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.891	98.899	98.906	0.010607	98.897	98.905	98.912	0.010607	0.006	0.006	0.006	0
50	98.889	98.895	98.906	0.0054423	98.89	98.899	98.91	0.006	0.001	0.0035714	0.007	0.0019024
100	98.885	98.895	98.9	0.0056214	98.886	98.899	98.905	0.0069761	0.001	0.0036667	0.005	0.0020656

Device Test: 6.102 VOH_RESET_10MA(VOH_10mA_RESETB2/RESETB2/7/3/0/0/10/@VOH_RESET_10MA)





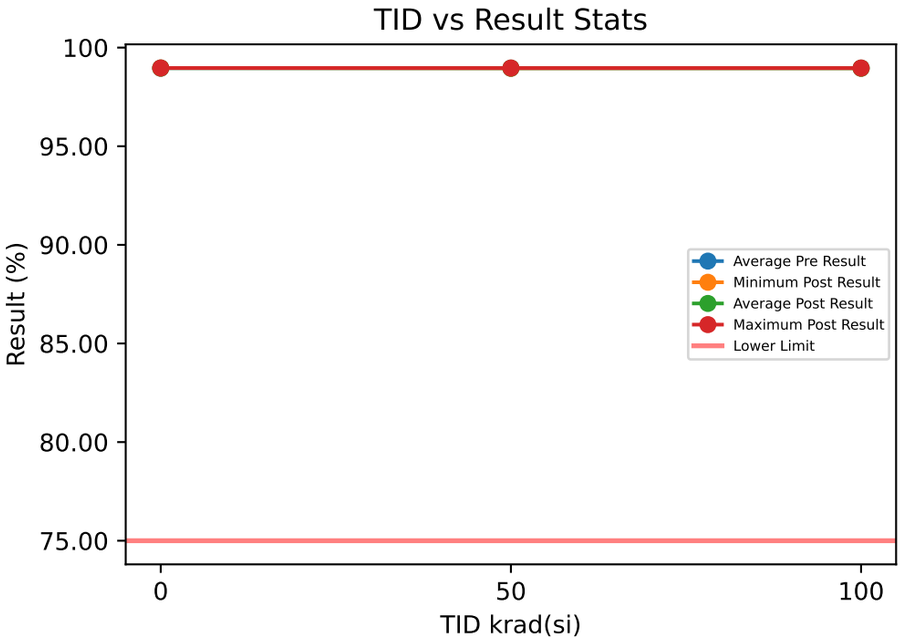
Test Results (Lower Limit = 75.0 (%))

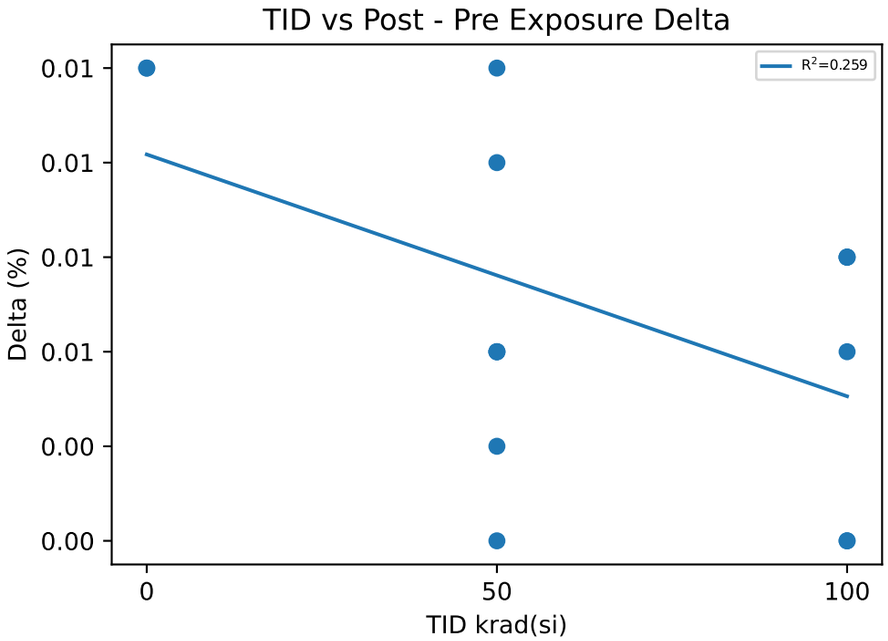
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	98.909	98.915	0.006
89	50	Biased	98.91	98.914	0.004
90	50	Biased	98.906	98.91	0.004
92	50	Biased	98.902	98.902	0
93	50	Unbiased	98.906	98.909	0.003
94	50	Unbiased	98.906	98.908	0.002
95	50	Unbiased	98.913	98.916	0.003
96	100	Biased	98.899	98.9	0.001
97	100	Biased	98.907	98.91	0.003
98	100	Biased	98.91	98.913	0.003
99	100	Unbiased	98.909	98.913	0.004
100	100	Unbiased	98.904	98.908	0.004
101	100	Unbiased	98.912	98.913	0.001
102	0	Correlation	98.916	98.921	0.005
103	0	Correlation	98.903	98.91	0.007

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.903	98.91	98.916	0.0091924	98.91	98.916	98.921	0.0077782	0.005	0.006	0.007	0.0014142
50	98.902	98.907	98.913	0.0035523	98.902	98.911	98.916	0.0048941	0	0.0031429	0.006	0.0018645
100	98.899	98.907	98.912	0.0047081	98.9	98.909	98.913	0.0050892	0.001	0.0026667	0.004	0.0013663

Device Test: 6.103 VOH_RESET_10MA(VOH_10mA_RESETB3/RESETB3/7/3/0/0/10/@VOH_RESET_10MA)





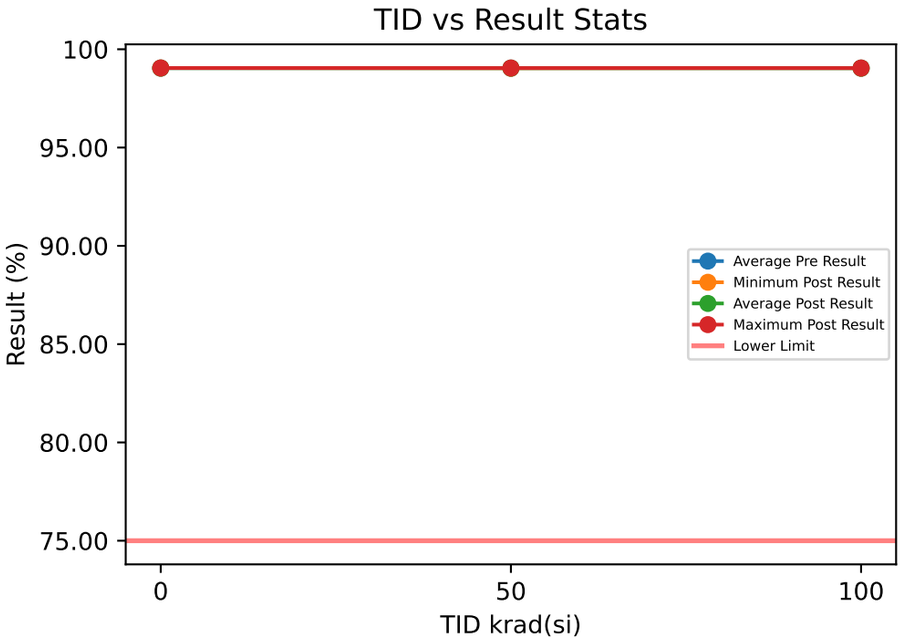
Test Results (Lower Limit = 75.0 (%))

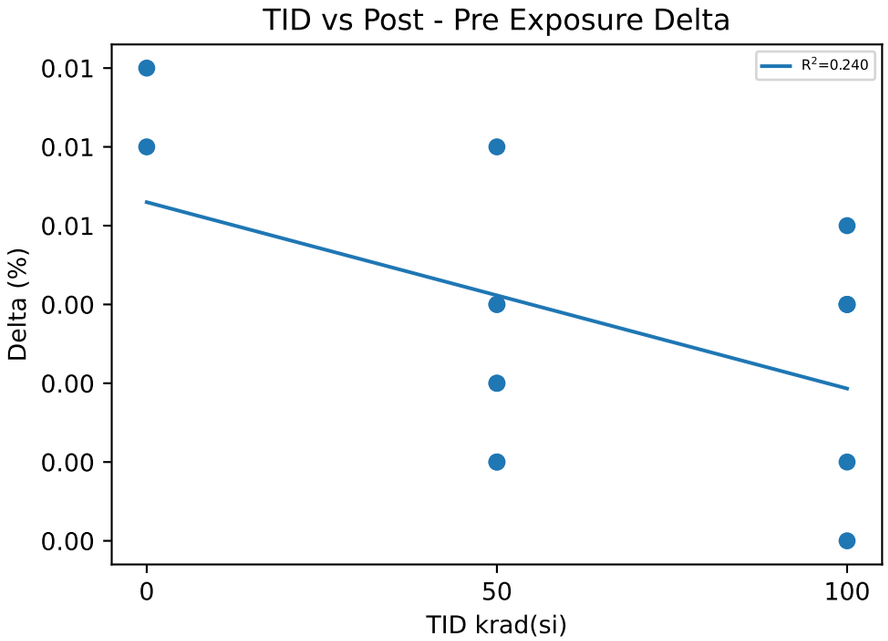
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	98.957	98.965	0.008
89	50	Biased	98.958	98.963	0.005
90	50	Biased	98.956	98.961	0.005
92	50	Biased	98.948	98.951	0.003
93	50	Unbiased	98.954	98.959	0.005
94	50	Unbiased	98.955	98.959	0.004
95	50	Unbiased	98.955	98.962	0.007
96	100	Biased	98.949	98.952	0.003
97	100	Biased	98.953	98.959	0.006
98	100	Biased	98.96	98.965	0.005
99	100	Unbiased	98.958	98.964	0.006
100	100	Unbiased	98.953	98.959	0.006
101	100	Unbiased	98.954	98.957	0.003
102	0	Correlation	98.959	98.967	0.008
103	0	Correlation	98.952	98.96	0.008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.952	98.956	98.959	0.0049497	98.96	98.963	98.967	0.0049497	0.008	0.008	0.008	0
50	98.948	98.955	98.958	0.0032514	98.951	98.96	98.965	0.0045092	0.003	0.0052857	0.008	0.0017043
100	98.949	98.954	98.96	0.003937	98.952	98.959	98.965	0.004761	0.003	0.0048333	0.006	0.001472

Device Test: 6.104 VOH_RESET_10MA(VOH_10mA_RESETB4/RESETB4/7/3/0/0/10/@VOH_RESET_10MA)





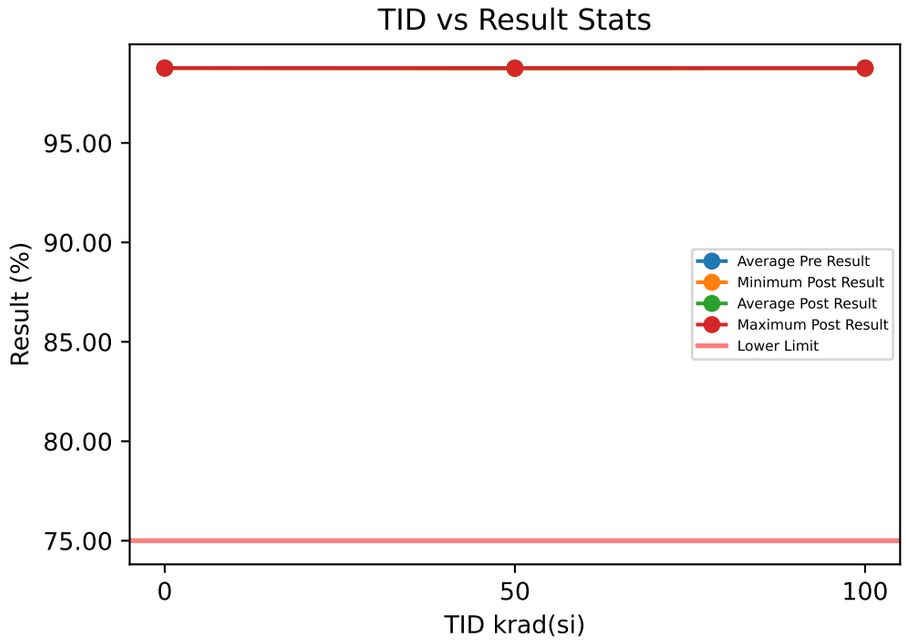
Test Results (Lower Limit = 75.0 (%))

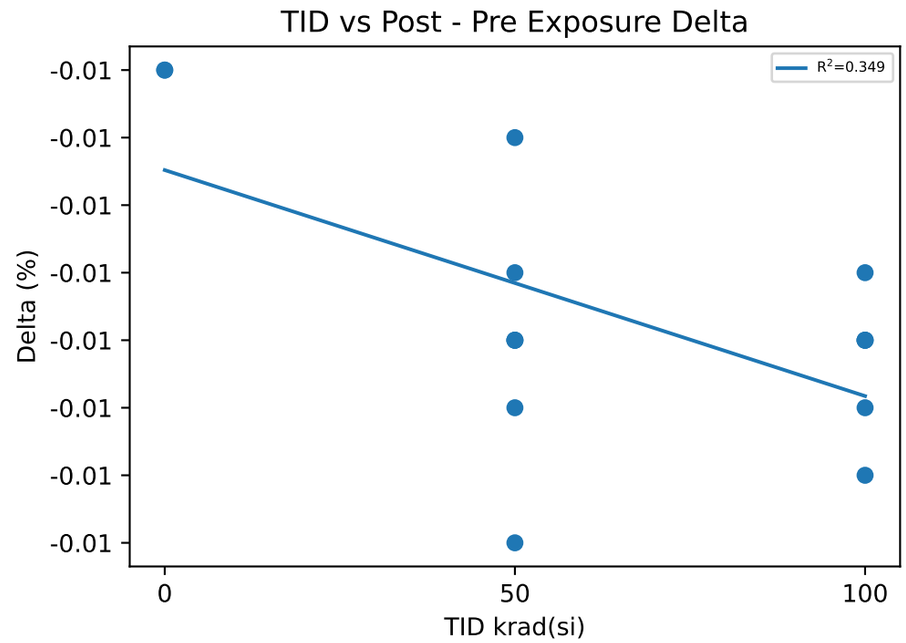
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.039	99.045	0.006
89	50	Biased	99.041	99.044	0.003
90	50	Biased	99.042	99.046	0.004
92	50	Biased	99.031	99.033	0.002
93	50	Unbiased	99.036	99.039	0.003
94	50	Unbiased	99.039	99.041	0.002
95	50	Unbiased	99.041	99.045	0.004
96	100	Biased	99.035	99.037	0.002
97	100	Biased	99.038	99.043	0.005
98	100	Biased	99.041	99.045	0.004
99	100	Unbiased	99.04	99.044	0.004
100	100	Unbiased	99.035	99.039	0.004
101	100	Unbiased	99.038	99.039	0.001
102	0	Correlation	99.042	99.048	0.006
103	0	Correlation	99.034	99.041	0.007

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.034	99.038	99.042	0.0056569	99.041	99.044	99.048	0.0049497	0.006	0.0065	0.007	0.00070711
50	99.031	99.038	99.042	0.0038235	99.033	99.042	99.046	0.0046342	0.002	0.0034286	0.006	0.0013973
100	99.035	99.038	99.041	0.0024833	99.037	99.041	99.045	0.0032506	0.001	0.0033333	0.005	0.0015055

Device Test: 6.105 VOH_WDO_10MA(VOH_10mA_WDOB/WDOB/7/3/0/0/10/@VOH_WDO_10MA)





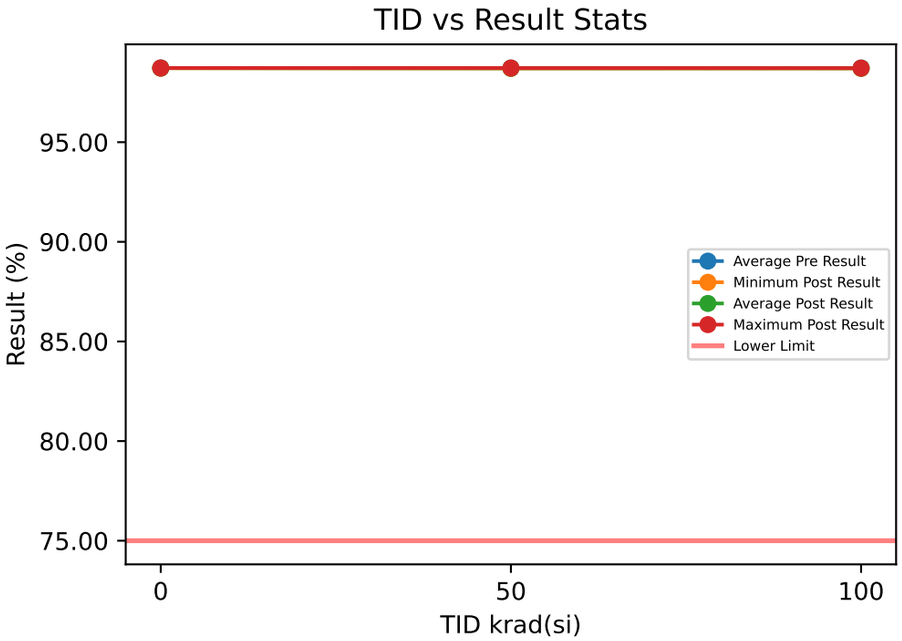
Test Results (Lower Limit = 75.0 (%))

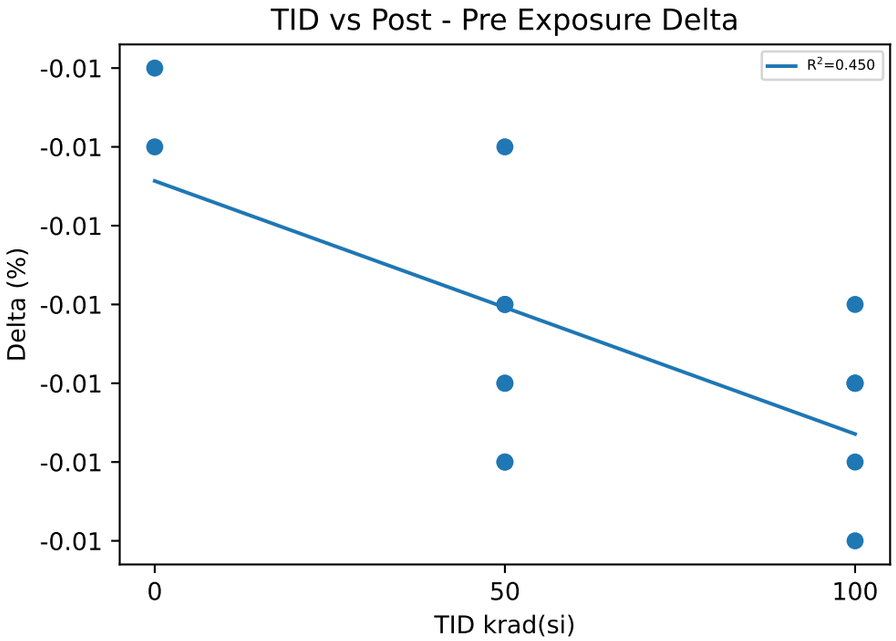
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	98.774	98.765	-0.009
89	50	Biased	98.769	98.757	-0.012
90	50	Biased	98.772	98.76	-0.012
92	50	Biased	98.759	98.744	-0.015
93	50	Unbiased	98.766	98.753	-0.013
94	50	Unbiased	98.77	98.758	-0.012
95	50	Unbiased	98.767	98.756	-0.011
96	100	Biased	98.766	98.753	-0.013
97	100	Biased	98.77	98.758	-0.012
98	100	Biased	98.77	98.758	-0.012
99	100	Unbiased	98.776	98.765	-0.011
100	100	Unbiased	98.773	98.761	-0.012
101	100	Unbiased	98.769	98.755	-0.014
102	0	Correlation	98.778	98.77	-0.008
103	0	Correlation	98.763	98.755	-0.008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.763	98.77	98.778	0.010607	98.755	98.762	98.77	0.010607	-0.008	-0.008	-0.008	0
50	98.759	98.768	98.774	0.0048795	98.744	98.756	98.765	0.0065174	-0.015	-0.012	-0.009	0.0018257
100	98.766	98.771	98.776	0.0034448	98.753	98.758	98.765	0.004274	-0.014	-0.012333	-0.011	0.0010328

Device Test: 6.106 VOH_PWRGD_10MA(VOH_10mA_PWRGD/PWRGD/7/3/0/0/10/@VOH_PWRGD_10MA)





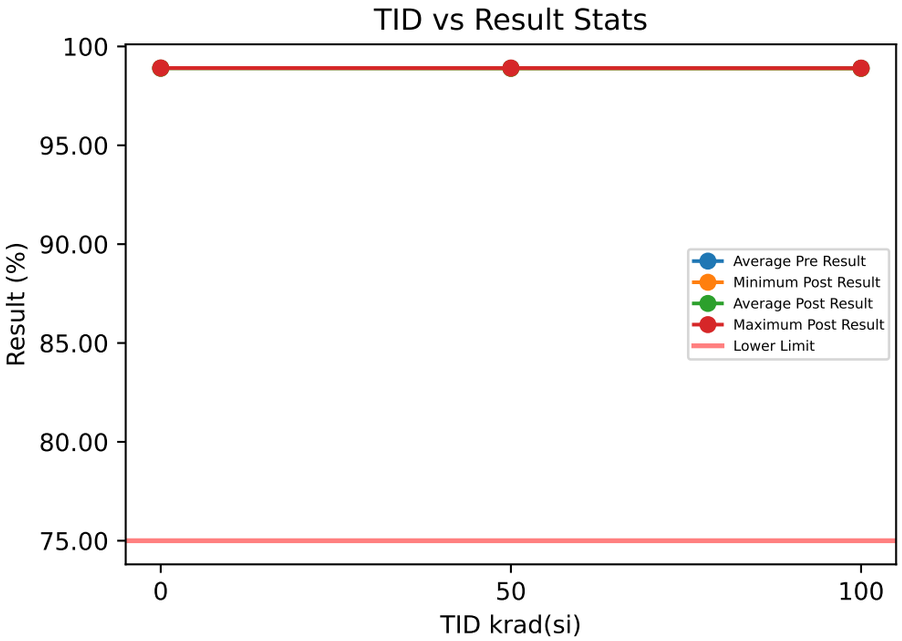
Test Results (Lower Limit = 75.0 (%))

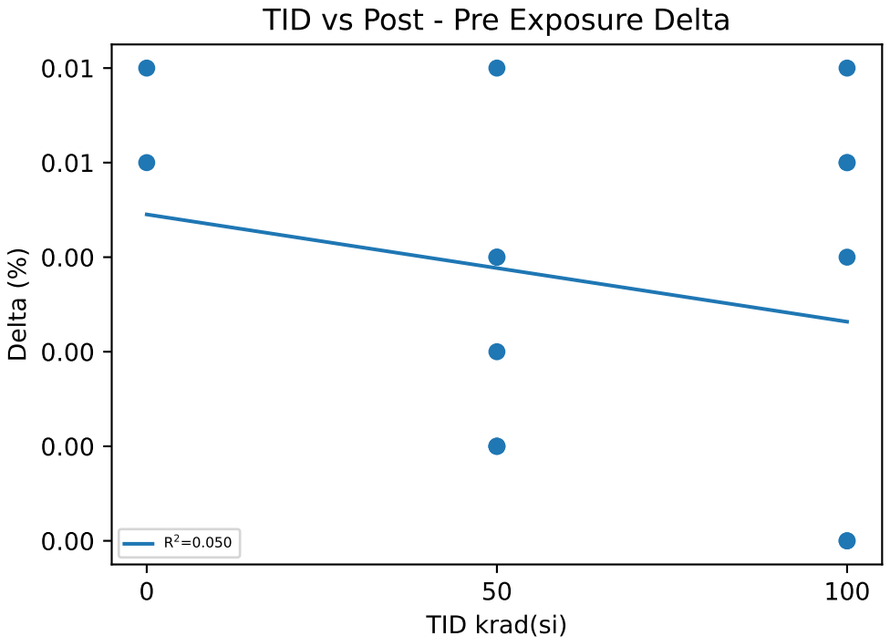
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	98.728	98.722	-0.006
89	50	Biased	98.72	98.711	-0.009
90	50	Biased	98.721	98.712	-0.009
92	50	Biased	98.709	98.699	-0.01
93	50	Unbiased	98.72	98.71	-0.01
94	50	Unbiased	98.719	98.711	-0.008
95	50	Unbiased	98.723	98.715	-0.008
96	100	Biased	98.711	98.701	-0.01
97	100	Biased	98.72	98.711	-0.009
98	100	Biased	98.727	98.718	-0.009
99	100	Unbiased	98.725	98.717	-0.008
100	100	Unbiased	98.723	98.714	-0.009
101	100	Unbiased	98.726	98.715	-0.011
102	0	Correlation	98.73	98.724	-0.006
103	0	Correlation	98.717	98.712	-0.005

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.717	98.724	98.73	0.0091924	98.712	98.718	98.724	0.0084853	-0.006	-0.0055	-0.005	0.00070711
50	98.709	98.72	98.728	0.0057155	98.699	98.711	98.722	0.0068522	-0.01	-0.0085714	-0.006	0.0013973
100	98.711	98.722	98.727	0.005933	98.701	98.713	98.718	0.0062183	-0.011	-0.0093333	-0.008	0.0010328

Device Test: 6.107 VOH_RESET_10MA(VOH_10mA_RESETB1/RESETB1/7/14/0/0/10/@VOH_RESET_10MA)





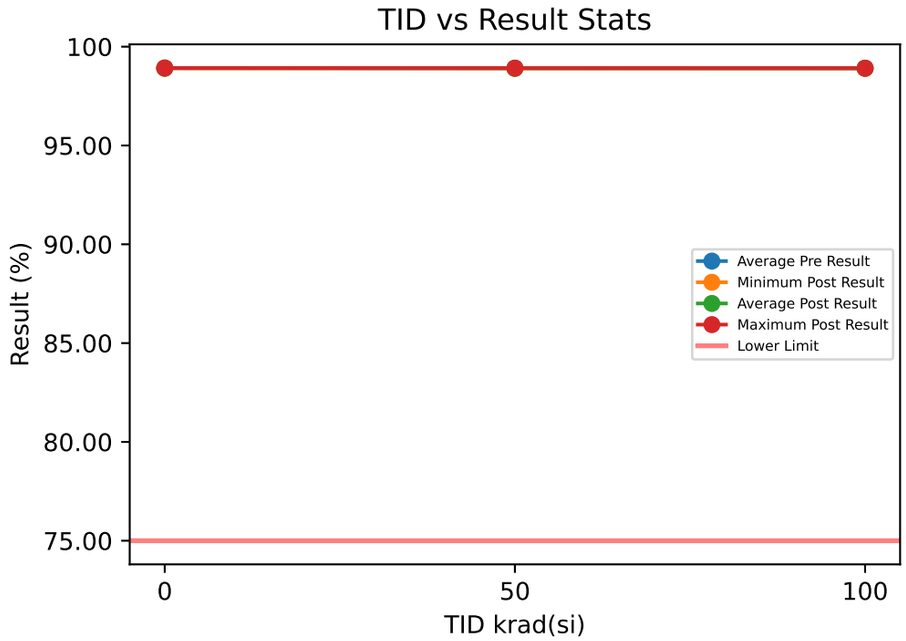
Test Results (Lower Limit = 75.0 (%))

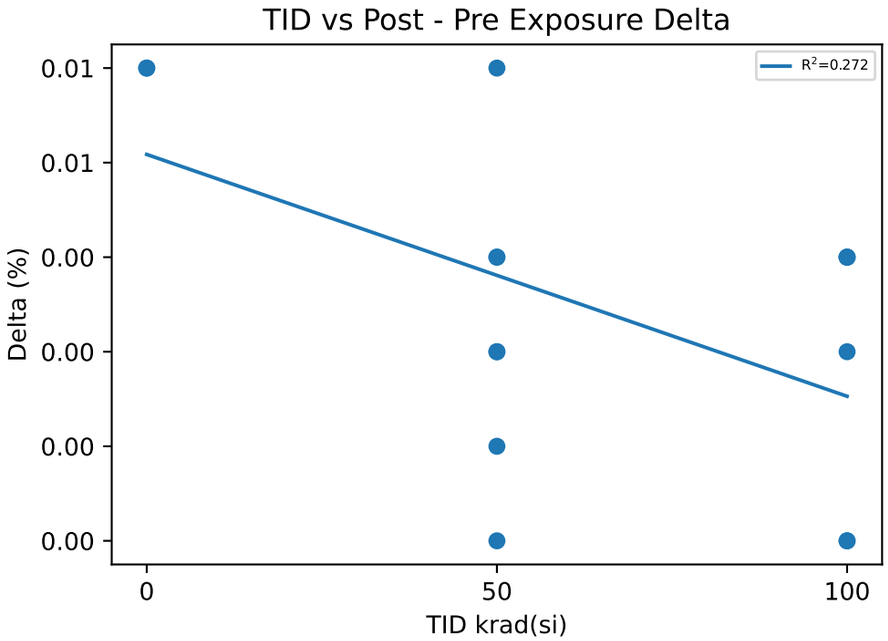
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	98.892	98.898	0.006
89	50	Biased	98.894	98.898	0.004
90	50	Biased	98.897	98.901	0.004
92	50	Biased	98.888	98.89	0.002
93	50	Unbiased	98.897	98.899	0.002
94	50	Unbiased	98.893	98.895	0.002
95	50	Unbiased	98.906	98.909	0.003
96	100	Biased	98.885	98.886	0.001
97	100	Biased	98.898	98.904	0.006
98	100	Biased	98.9	98.905	0.005
99	100	Unbiased	98.897	98.902	0.005
100	100	Unbiased	98.892	98.896	0.004
101	100	Unbiased	98.897	98.898	0.001
102	0	Correlation	98.906	98.911	0.005
103	0	Correlation	98.891	98.897	0.006

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.891	98.899	98.906	0.010607	98.897	98.904	98.911	0.0098995	0.005	0.0055	0.006	0.00070711
50	98.888	98.895	98.906	0.0056484	98.89	98.899	98.909	0.0057982	0.002	0.0032857	0.006	0.001496
100	98.885	98.895	98.9	0.0054924	98.886	98.898	98.905	0.0070356	0.001	0.0036667	0.006	0.0021602

Device Test: 6.108 VOH_RESET_10MA(VOH_10mA_RESETB2/RESETB2/7/14/0/0/10/@VOH_RESET_10MA)





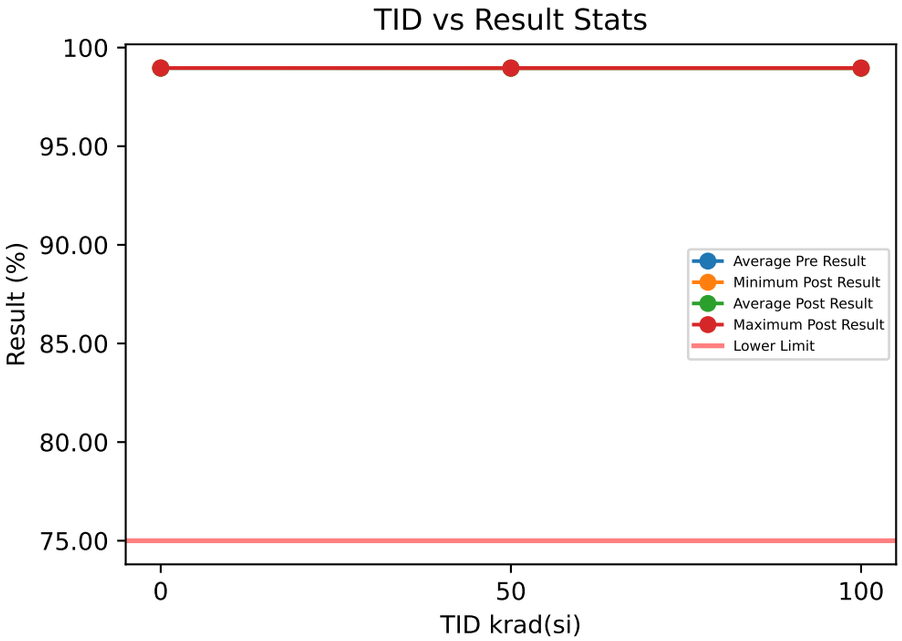
Test Results (Lower Limit = 75.0 (%))

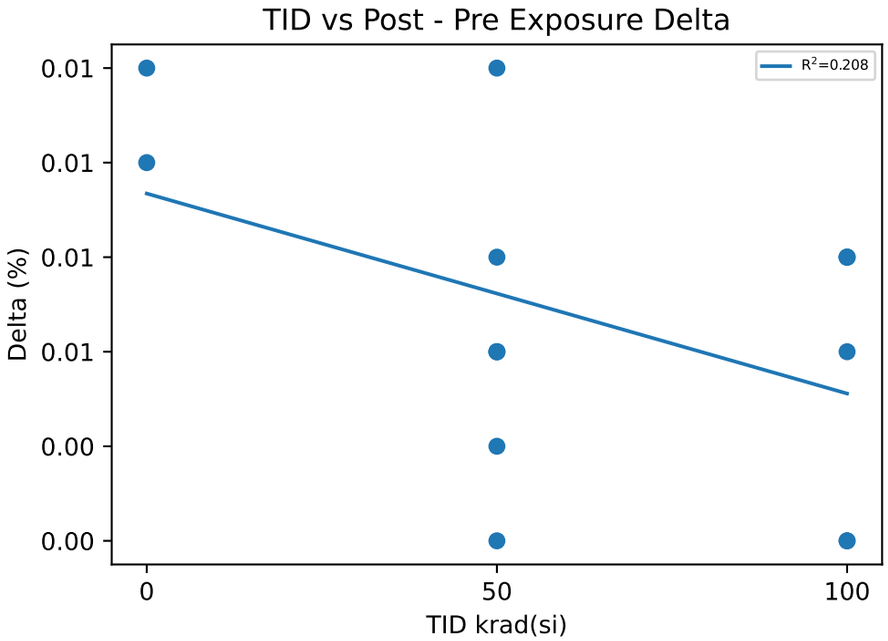
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	98.909	98.915	0.006
89	50	Biased	98.91	98.914	0.004
90	50	Biased	98.906	98.91	0.004
92	50	Biased	98.901	98.902	0.001
93	50	Unbiased	98.906	98.908	0.002
94	50	Unbiased	98.905	98.908	0.003
95	50	Unbiased	98.913	98.916	0.003
96	100	Biased	98.899	98.9	0.001
97	100	Biased	98.906	98.91	0.004
98	100	Biased	98.91	98.913	0.003
99	100	Unbiased	98.909	98.913	0.004
100	100	Unbiased	98.904	98.908	0.004
101	100	Unbiased	98.912	98.913	0.001
102	0	Correlation	98.916	98.922	0.006
103	0	Correlation	98.903	98.909	0.006

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.903	98.91	98.916	0.0091924	98.909	98.916	98.922	0.0091924	0.006	0.006	0.006	0
50	98.901	98.907	98.913	0.0038914	98.902	98.91	98.916	0.0049618	0.001	0.0032857	0.006	0.0016036
100	98.899	98.907	98.912	0.0047188	98.9	98.909	98.913	0.0050892	0.001	0.0028333	0.004	0.001472

Device Test: 6.109 VOH_RESET_10MA(VOH_10mA_RESETB3/RESETB3/7/14/0/0/10/@VOH_RESET_10MA)





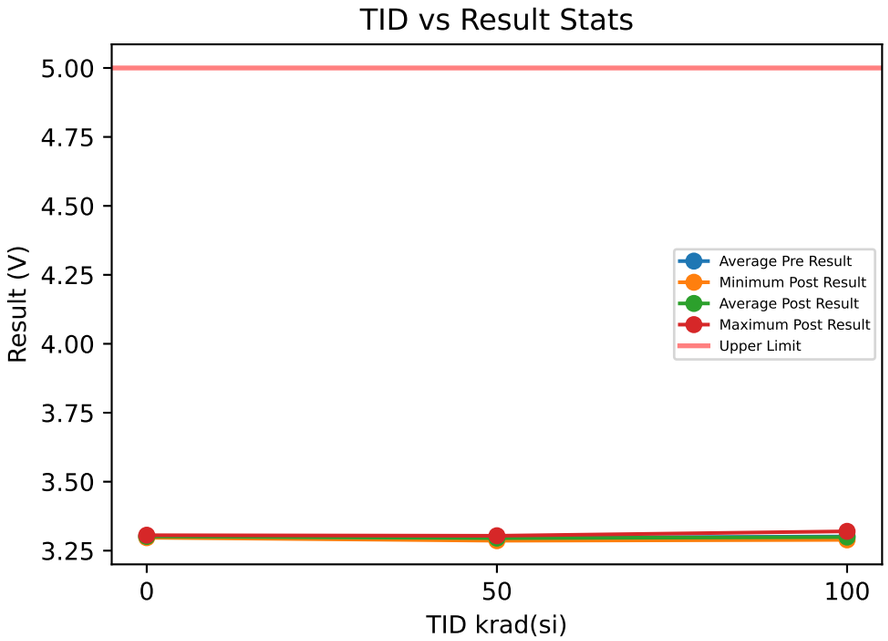
Test Results (Lower Limit = 75.0 (%))

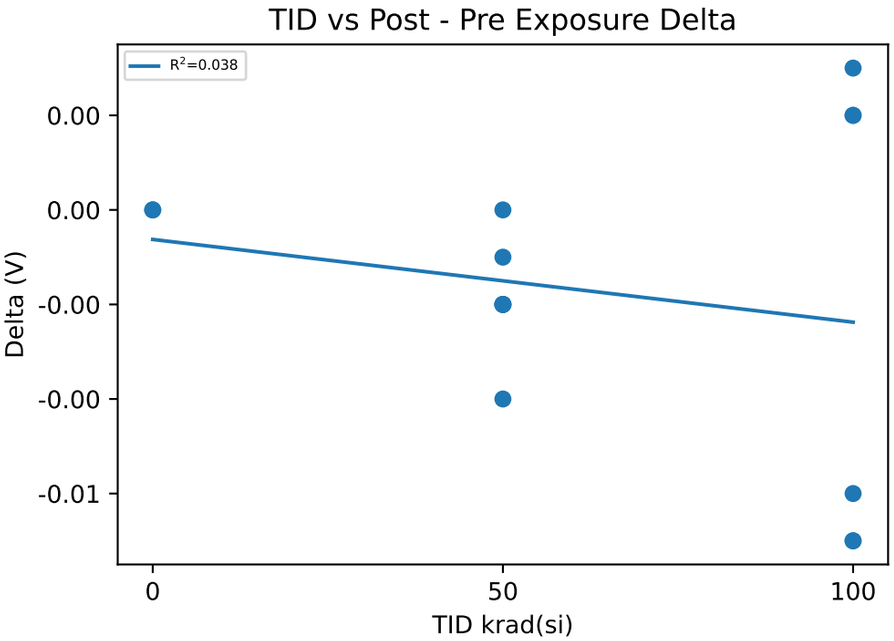
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	98.957	98.965	0.008
89	50	Biased	98.958	98.963	0.005
90	50	Biased	98.955	98.961	0.006
92	50	Biased	98.948	98.951	0.003
93	50	Unbiased	98.954	98.958	0.004
94	50	Unbiased	98.954	98.959	0.005
95	50	Unbiased	98.956	98.961	0.005
96	100	Biased	98.949	98.952	0.003
97	100	Biased	98.953	98.959	0.006
98	100	Biased	98.96	98.965	0.005
99	100	Unbiased	98.958	98.964	0.006
100	100	Unbiased	98.953	98.959	0.006
101	100	Unbiased	98.954	98.957	0.003
102	0	Correlation	98.959	98.966	0.007
103	0	Correlation	98.952	98.96	0.008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.952	98.956	98.959	0.0049497	98.96	98.963	98.966	0.0042426	0.007	0.0075	0.008	0.00070711
50	98.948	98.955	98.958	0.0032587	98.951	98.96	98.965	0.0044987	0.003	0.0051429	0.008	0.0015736
100	98.949	98.954	98.96	0.003937	98.952	98.959	98.965	0.004761	0.003	0.0048333	0.006	0.001472

Device Test: 6.11 VLDO_I_MAX(VLDO_IMAX/VLDO//3/0/0/0/@VLDO_I_MAX)





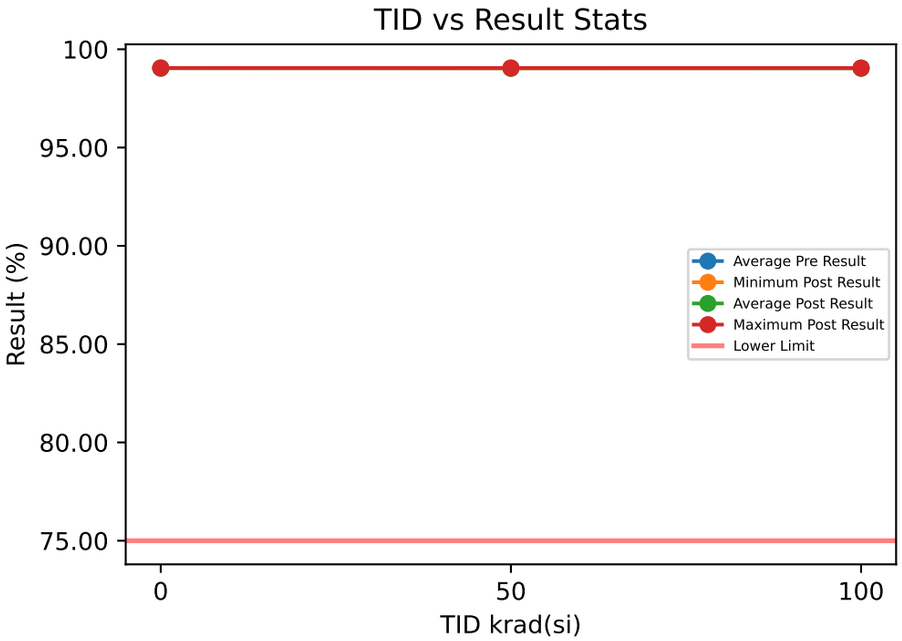
Test Results (Upper Limit = 5.0 (V))

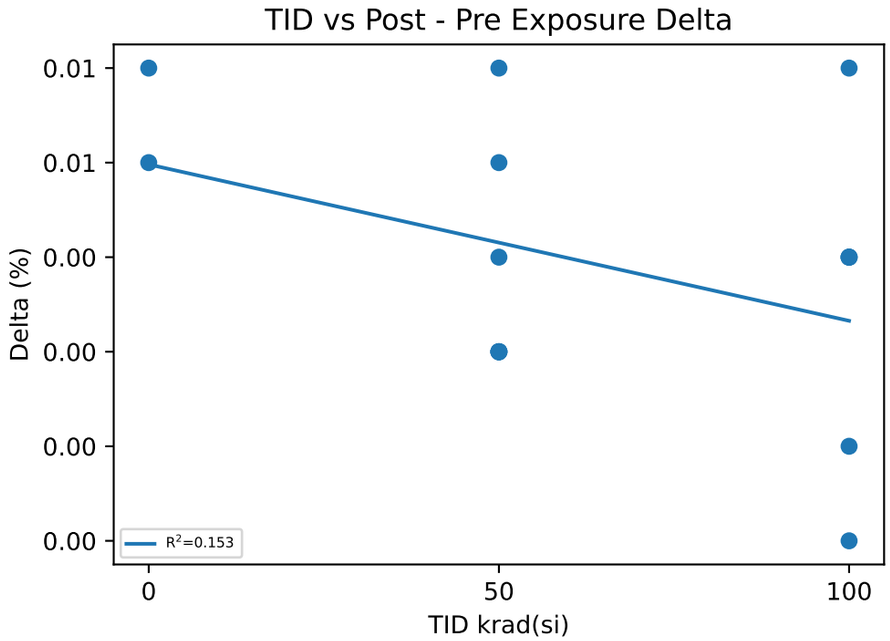
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	3.291	3.291	0
89	50	Biased	3.304	3.302	-0.002
90	50	Biased	3.288	3.286	-0.002
92	50	Biased	3.305	3.303	-0.002
93	50	Unbiased	3.308	3.304	-0.004
94	50	Unbiased	3.29	3.289	-0.001
95	50	Unbiased	3.294	3.292	-0.002
96	100	Biased	3.303	3.296	-0.007
97	100	Biased	3.302	3.296	-0.006
98	100	Biased	3.317	3.32	0.003
99	100	Unbiased	3.297	3.299	0.002
100	100	Unbiased	3.293	3.295	0.002
101	100	Unbiased	3.296	3.289	-0.007
102	0	Correlation	3.306	3.306	0
103	0	Correlation	3.297	3.297	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.297	3.3015	3.306	0.006364	3.297	3.3015	3.306	0.006364	0	0	0	0
50	3.288	3.2971	3.308	0.0082549	3.286	3.2953	3.304	0.0074769	-0.004	-0.0018571	0	0.001215
100	3.293	3.3013	3.317	0.0085479	3.289	3.2992	3.32	0.010722	-0.007	-0.0021667	0.003	0.0049565

Device Test: 6.110 VOH_RESET_10MA(VOH_10mA_RESETB4/RESETB4/7/14/0/0/10/@VOH_RESET_10MA)





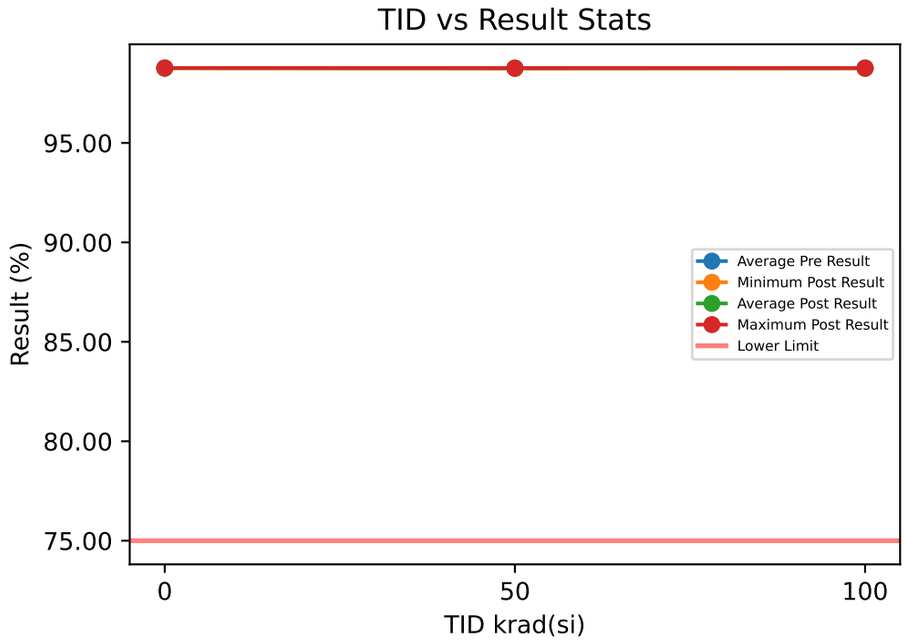
Test Results (Lower Limit = 75.0 (%))

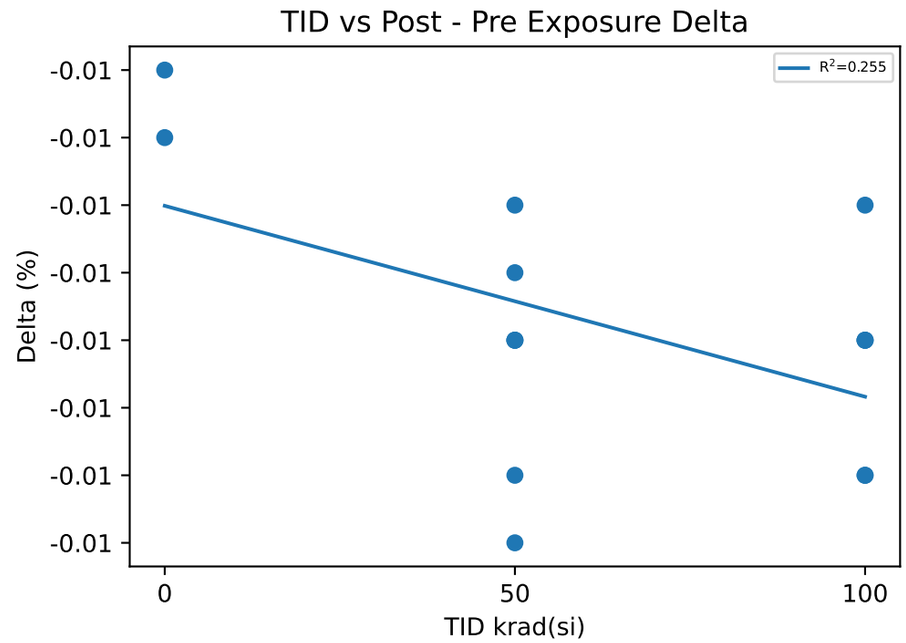
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.039	99.045	0.006
89	50	Biased	99.041	99.044	0.003
90	50	Biased	99.041	99.046	0.005
92	50	Biased	99.03	99.033	0.003
93	50	Unbiased	99.036	99.039	0.003
94	50	Unbiased	99.038	99.041	0.003
95	50	Unbiased	99.041	99.045	0.004
96	100	Biased	99.035	99.037	0.002
97	100	Biased	99.037	99.043	0.006
98	100	Biased	99.041	99.045	0.004
99	100	Unbiased	99.04	99.044	0.004
100	100	Unbiased	99.035	99.039	0.004
101	100	Unbiased	99.038	99.039	0.001
102	0	Correlation	99.042	99.048	0.006
103	0	Correlation	99.035	99.04	0.005

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.035	99.038	99.042	0.0049497	99.04	99.044	99.048	0.0056569	0.005	0.0055	0.006	0.00070711
50	99.03	99.038	99.041	0.004	99.033	99.042	99.046	0.0046342	0.003	0.0038571	0.006	0.001215
100	99.035	99.038	99.041	0.0025033	99.037	99.041	99.045	0.0032506	0.001	0.0035	0.006	0.0017607

Device Test: 6.111 VOH_WDO_10MA(VOH_10mA_WDOB/WDOB/7/14/0/0/10/@VOH_WDO_10MA)





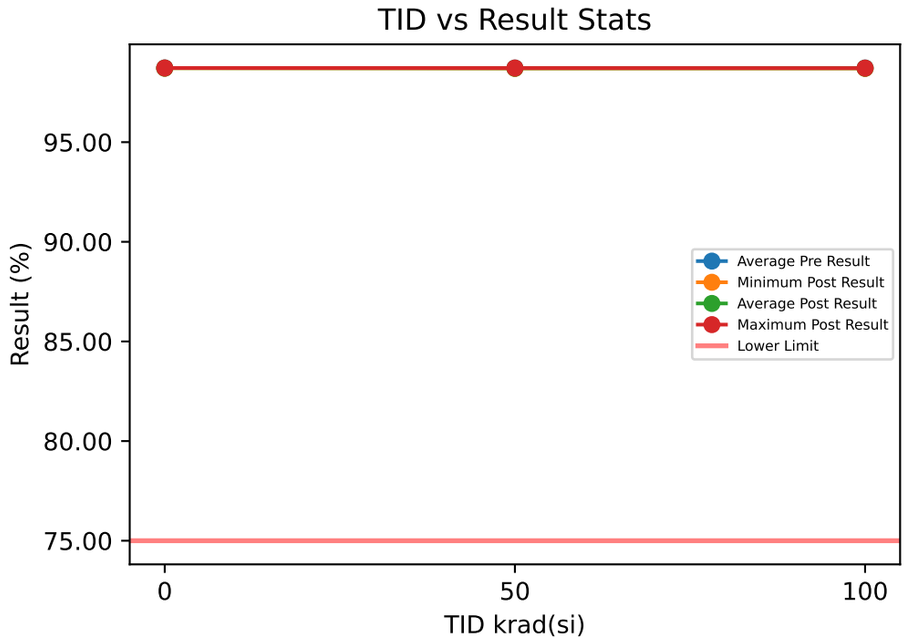
Test Results (Lower Limit = 75.0 (%))

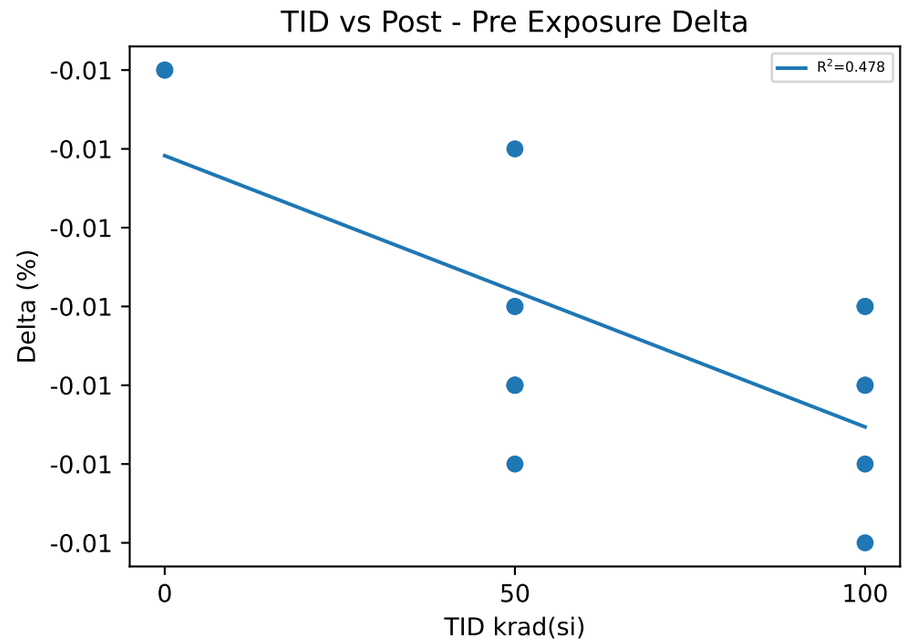
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	98.774	98.764	-0.01
89	50	Biased	98.768	98.756	-0.012
90	50	Biased	98.771	98.76	-0.011
92	50	Biased	98.758	98.743	-0.015
93	50	Unbiased	98.766	98.752	-0.014
94	50	Unbiased	98.769	98.757	-0.012
95	50	Unbiased	98.767	98.755	-0.012
96	100	Biased	98.765	98.751	-0.014
97	100	Biased	98.769	98.757	-0.012
98	100	Biased	98.769	98.757	-0.012
99	100	Unbiased	98.775	98.765	-0.01
100	100	Unbiased	98.772	98.76	-0.012
101	100	Unbiased	98.768	98.754	-0.014
102	0	Correlation	98.777	98.769	-0.008
103	0	Correlation	98.763	98.754	-0.009

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.763	98.77	98.777	0.0098995	98.754	98.762	98.769	0.010607	-0.009	-0.0085	-0.008	0.00070711
50	98.758	98.768	98.774	0.0049952	98.743	98.755	98.764	0.0066261	-0.015	-0.012286	-0.01	0.0017043
100	98.765	98.77	98.775	0.0034448	98.751	98.757	98.765	0.0048442	-0.014	-0.012333	-0.01	0.0015055

Device Test: 6.112 VOH_PWRGD_10MA(VOH_10mA_PWRGD/PWRGD/7/14/0/0/10/@VOH_PWRGD_10MA)





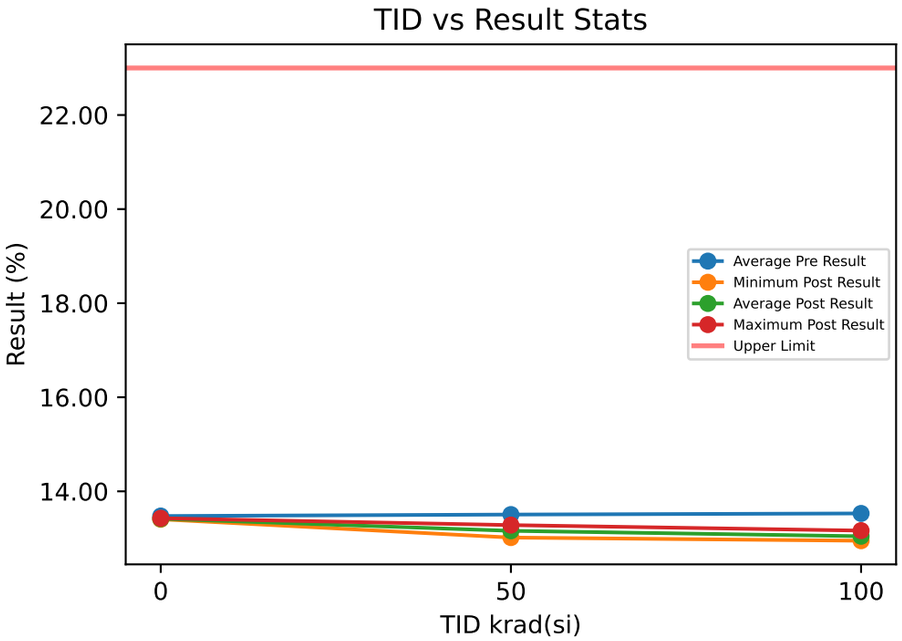
Test Results (Lower Limit = 75.0 (%))

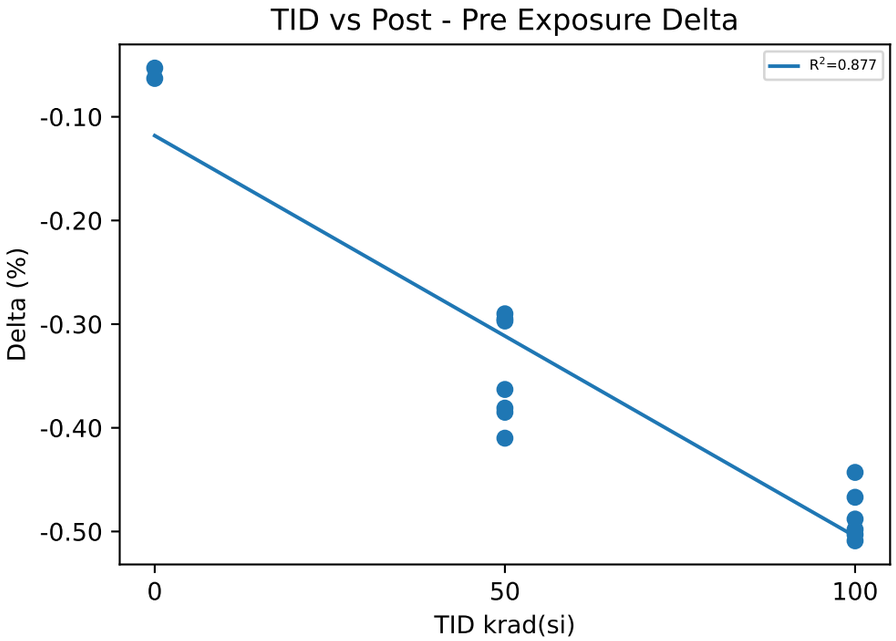
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	98.727	98.721	-0.006
89	50	Biased	98.719	98.71	-0.009
90	50	Biased	98.72	98.712	-0.008
92	50	Biased	98.708	98.698	-0.01
93	50	Unbiased	98.719	98.71	-0.009
94	50	Unbiased	98.718	98.709	-0.009
95	50	Unbiased	98.722	98.714	-0.008
96	100	Biased	98.71	98.7	-0.01
97	100	Biased	98.719	98.711	-0.008
98	100	Biased	98.726	98.717	-0.009
99	100	Unbiased	98.724	98.716	-0.008
100	100	Unbiased	98.722	98.713	-0.009
101	100	Unbiased	98.725	98.714	-0.011
102	0	Correlation	98.728	98.723	-0.005
103	0	Correlation	98.716	98.711	-0.005

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.716	98.722	98.728	0.0084853	98.711	98.717	98.723	0.0084853	-0.005	-0.005	-0.005	0
50	98.708	98.719	98.727	0.0057155	98.698	98.711	98.721	0.0068765	-0.01	-0.0084286	-0.006	0.0012724
100	98.71	98.721	98.726	0.005933	98.7	98.712	98.717	0.0061779	-0.011	-0.0091667	-0.008	0.001169

Device Test: 6.113 VOL_RESET_10MA(VOL_10mA_RESETB1/RESETB1/1.6/3/0/0/10/@VOL_RESET_10MA)





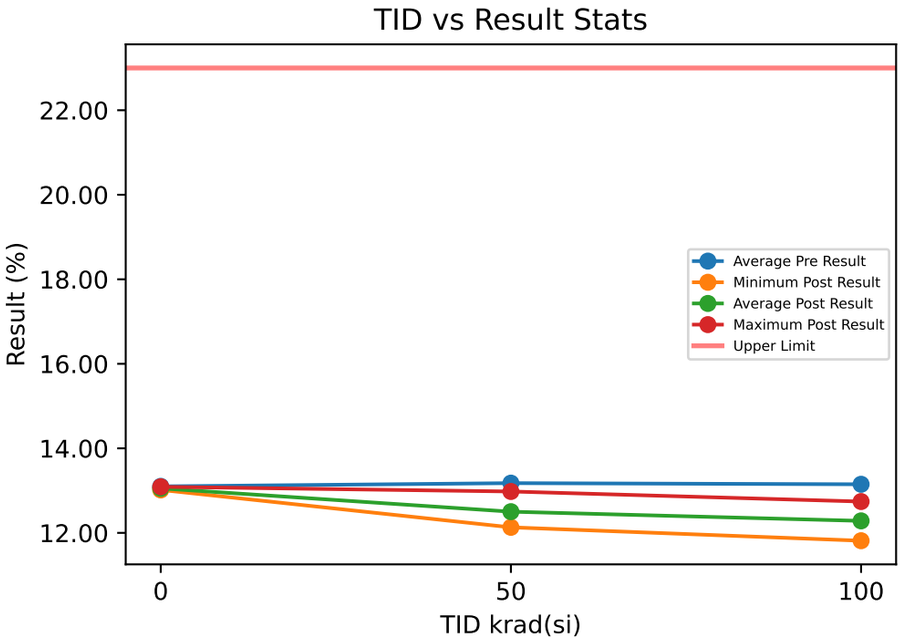
Test Results (Upper Limit = 23.0 (%))

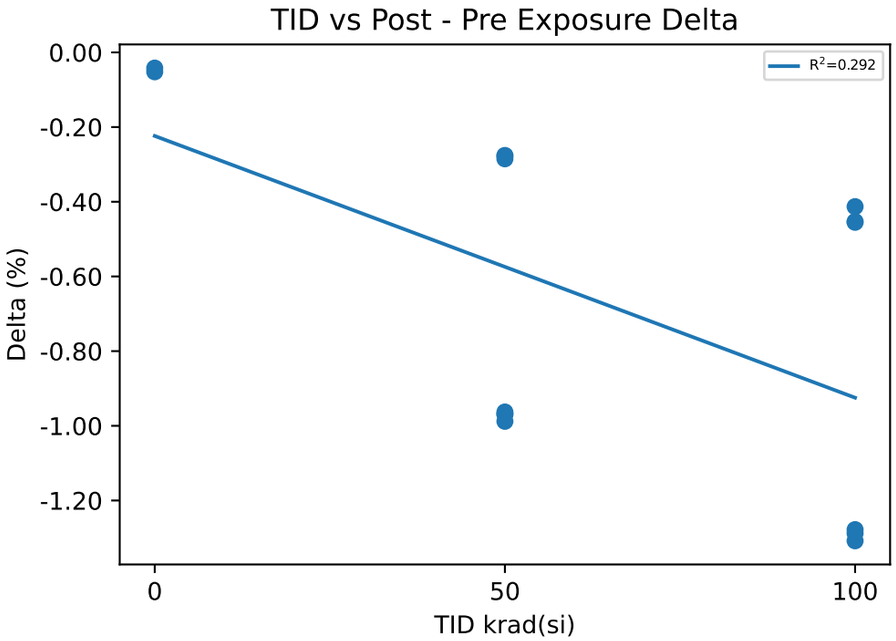
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	13.427	13.017	-0.41
89	50	Biased	13.504	13.123	-0.381
90	50	Biased	13.545	13.16	-0.385
92	50	Biased	13.441	13.078	-0.363
93	50	Unbiased	13.545	13.255	-0.29
94	50	Unbiased	13.577	13.282	-0.295
95	50	Unbiased	13.504	13.207	-0.297
96	100	Biased	13.59	13.092	-0.498
97	100	Biased	13.453	12.95	-0.503
98	100	Biased	13.462	12.953	-0.509
99	100	Unbiased	13.653	13.165	-0.488
100	100	Unbiased	13.494	13.027	-0.467
101	100	Unbiased	13.527	13.084	-0.443
102	0	Correlation	13.459	13.406	-0.053
103	0	Correlation	13.491	13.428	-0.063

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.459	13.475	13.491	0.022627	13.406	13.417	13.428	0.015556	-0.063	-0.058	-0.053	0.0070711
50	13.427	13.506	13.577	0.055613	13.017	13.16	13.282	0.095446	-0.41	-0.34586	-0.29	0.050446
100	13.453	13.53	13.653	0.078214	12.95	13.045	13.165	0.084785	-0.509	-0.48467	-0.443	0.025161

Device Test: 6.114 VOL_RESET_10MA(VOL_10mA_RESETB2/RESETB2/1.6/3/0/0/10/@VOL_RESET_10MA)





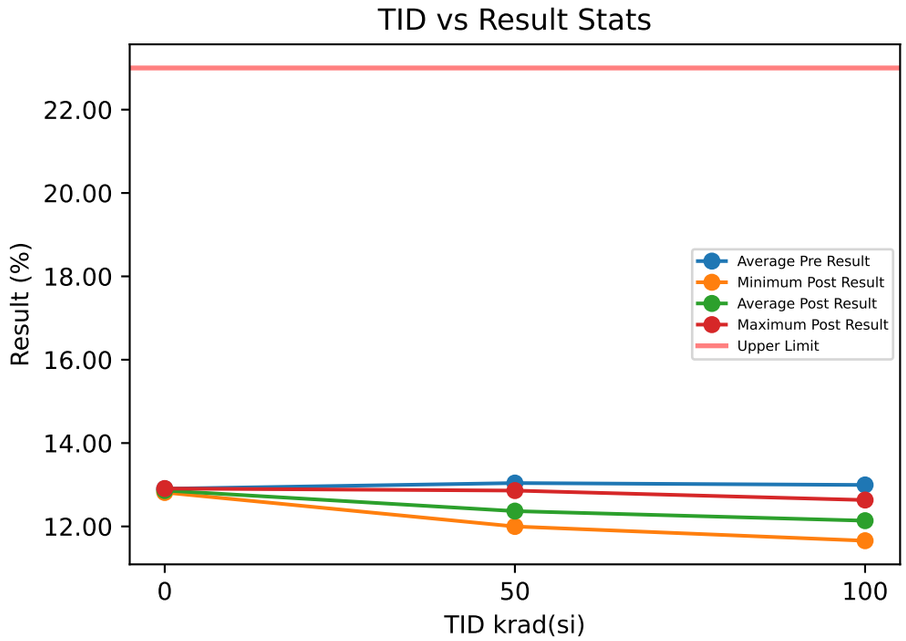
Test Results (Upper Limit = 23.0 (%))

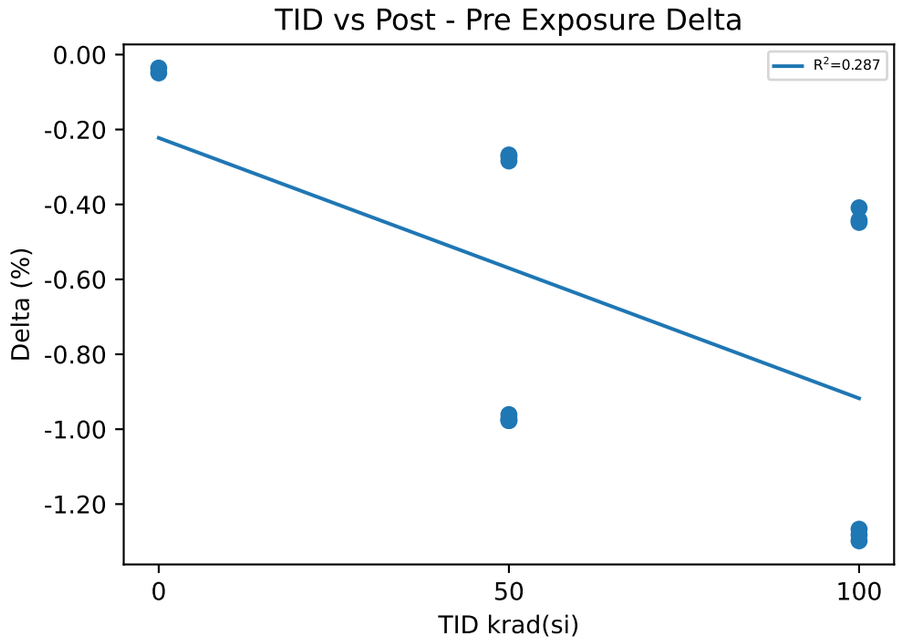
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	13.119	12.131	-0.988
89	50	Biased	13.151	12.188	-0.963
90	50	Biased	13.139	12.17	-0.969
92	50	Biased	13.304	12.335	-0.969
93	50	Unbiased	13.154	12.877	-0.277
94	50	Unbiased	13.264	12.979	-0.285
95	50	Unbiased	13.104	12.828	-0.276
96	100	Biased	13.149	11.871	-1.278
97	100	Biased	13.182	11.874	-1.308
98	100	Biased	13.102	11.814	-1.288
99	100	Unbiased	13.196	12.741	-0.455
100	100	Unbiased	13.176	12.723	-0.453
101	100	Unbiased	13.092	12.679	-0.413
102	0	Correlation	13.058	13.016	-0.042
103	0	Correlation	13.142	13.09	-0.052

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.058	13.1	13.142	0.059397	13.016	13.053	13.09	0.052326	-0.052	-0.047	-0.042	0.0070711
50	13.104	13.176	13.304	0.076417	12.131	12.501	12.979	0.37611	-0.988	-0.67529	-0.276	0.37047
100	13.092	13.15	13.196	0.043551	11.814	12.284	12.741	0.47269	-1.308	-0.86583	-0.413	0.46645

Device Test: 6.115 VOL_RESET_10MA(VOL_10mA_RESETB3/RESETB3/1.6/3/0/0/10/@VOL_RESET_10MA)





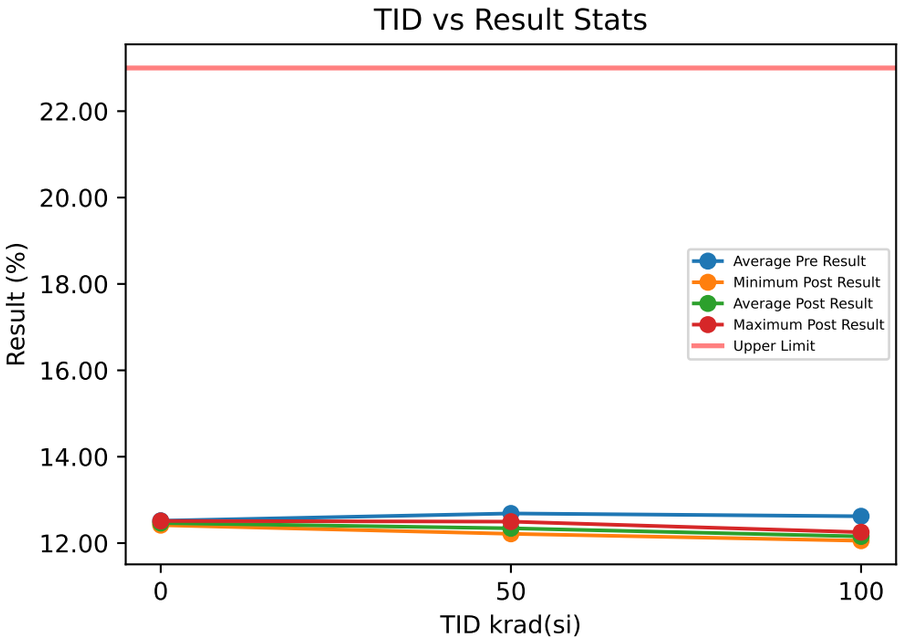
Test Results (Upper Limit = 23.0 (%))

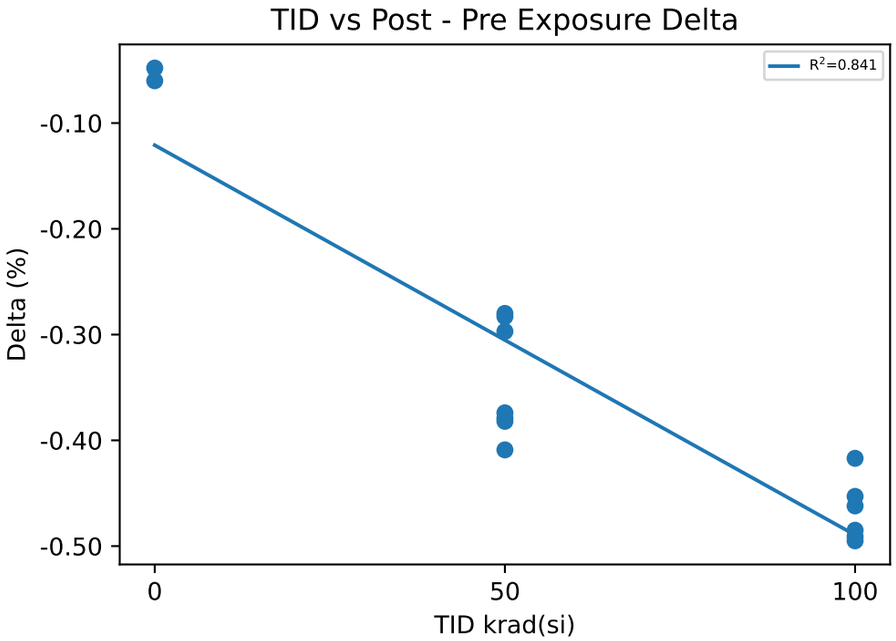
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.976	11.999	-0.977
89	50	Biased	13.042	12.071	-0.971
90	50	Biased	13.014	12.053	-0.961
92	50	Biased	13.163	12.186	-0.977
93	50	Unbiased	13.008	12.736	-0.272
94	50	Unbiased	13.144	12.86	-0.284
95	50	Unbiased	12.937	12.669	-0.268
96	100	Biased	13.029	11.762	-1.267
97	100	Biased	12.988	11.706	-1.282
98	100	Biased	12.955	11.657	-1.298
99	100	Unbiased	13.081	12.633	-0.448
100	100	Unbiased	12.968	12.526	-0.442
101	100	Unbiased	12.951	12.542	-0.409
102	0	Correlation	12.85	12.814	-0.036
103	0	Correlation	12.958	12.909	-0.049

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.85	12.904	12.958	0.076368	12.814	12.861	12.909	0.067175	-0.049	-0.0425	-0.036	0.0091924
50	12.937	13.041	13.163	0.084016	11.999	12.368	12.86	0.37077	-0.977	-0.67286	-0.268	0.37254
100	12.951	12.995	13.081	0.050725	11.657	12.138	12.633	0.47289	-1.298	-0.85767	-0.409	0.46549

Device Test: 6.116 VOL_RESET_10MA(VOL_10mA_RESETB4/RESETB4/1.6/3/0/0/10/@VOL_RESET_10MA)





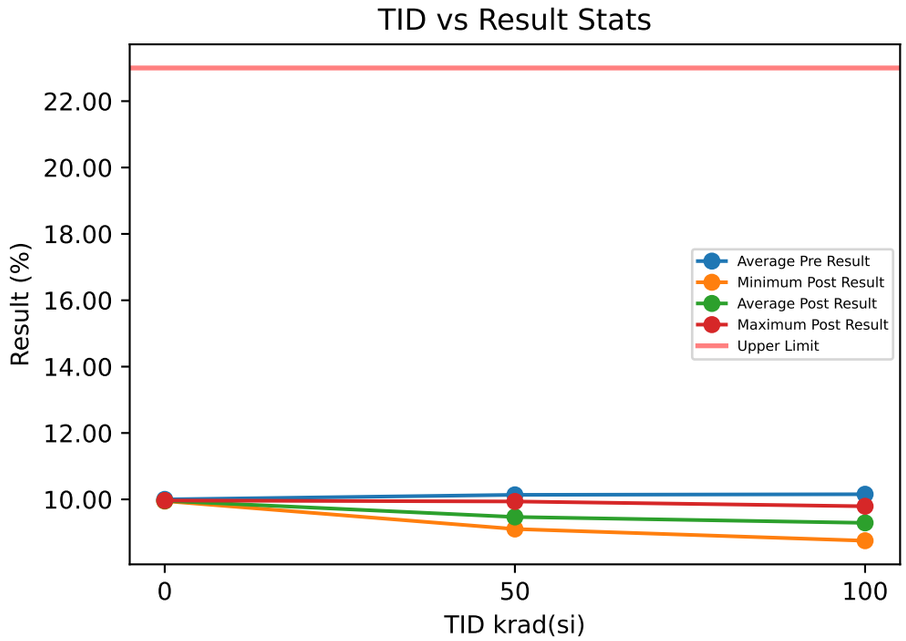
Test Results (Upper Limit = 23.0 (%))

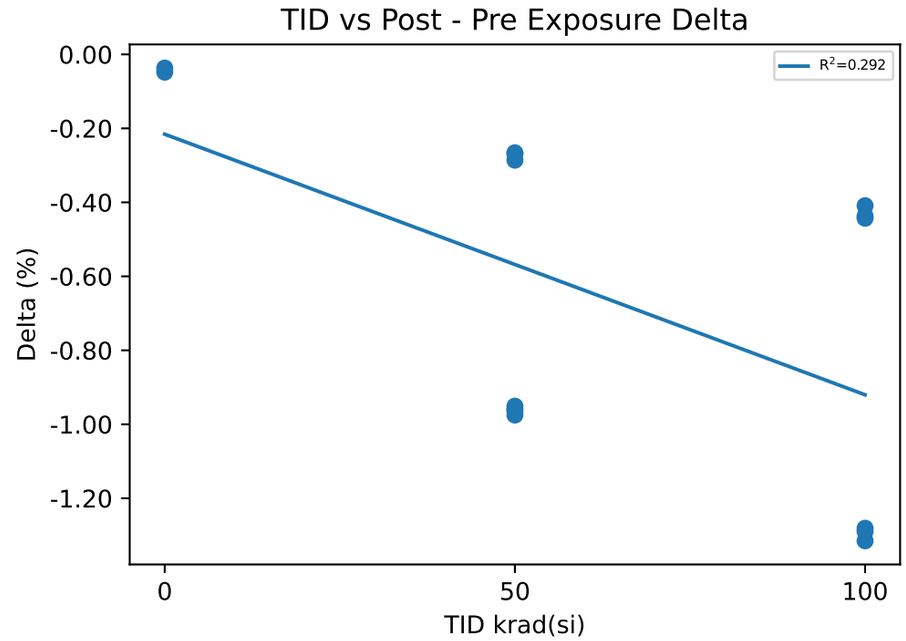
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.624	12.215	-0.409
89	50	Biased	12.648	12.266	-0.382
90	50	Biased	12.676	12.297	-0.379
92	50	Biased	12.871	12.497	-0.374
93	50	Unbiased	12.645	12.362	-0.283
94	50	Unbiased	12.774	12.477	-0.297
95	50	Unbiased	12.565	12.285	-0.28
96	100	Biased	12.699	12.214	-0.485
97	100	Biased	12.624	12.129	-0.495
98	100	Biased	12.546	12.055	-0.491
99	100	Unbiased	12.714	12.252	-0.462
100	100	Unbiased	12.585	12.132	-0.453
101	100	Unbiased	12.56	12.143	-0.417
102	0	Correlation	12.463	12.415	-0.048
103	0	Correlation	12.572	12.512	-0.06

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.463	12.517	12.572	0.077075	12.415	12.463	12.512	0.068589	-0.06	-0.054	-0.048	0.0084853
50	12.565	12.686	12.871	0.10302	12.215	12.343	12.497	0.10788	-0.409	-0.34343	-0.28	0.054494
100	12.546	12.621	12.714	0.071251	12.055	12.154	12.252	0.06962	-0.495	-0.46717	-0.417	0.029681

Device Test: 6.117 VOL_WDO_10MA(VOL_10mA_WDOB/WDOB/1.6/3/0/0/10/@VOL_WDO_10MA)





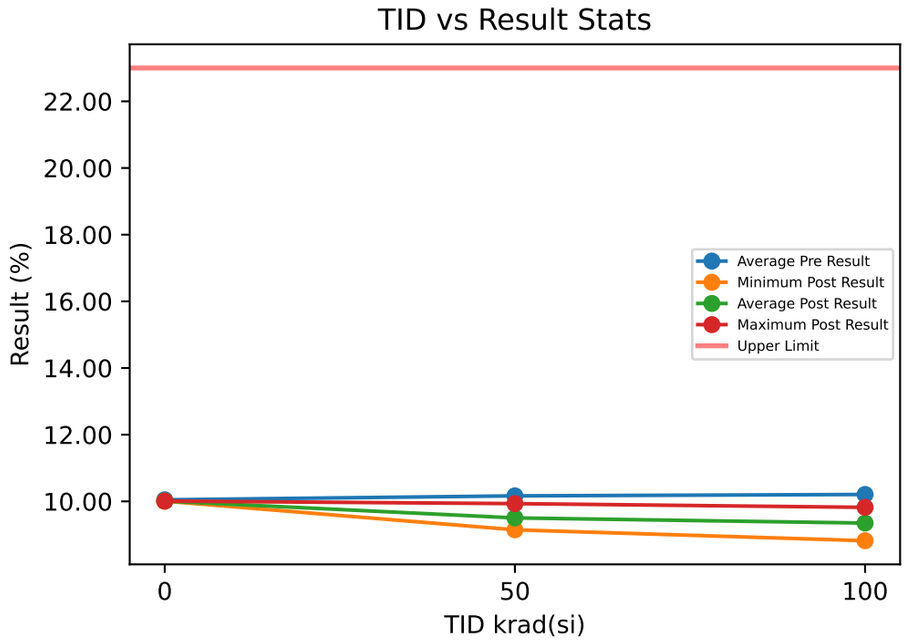
Test Results (Upper Limit = 23.0 (%))

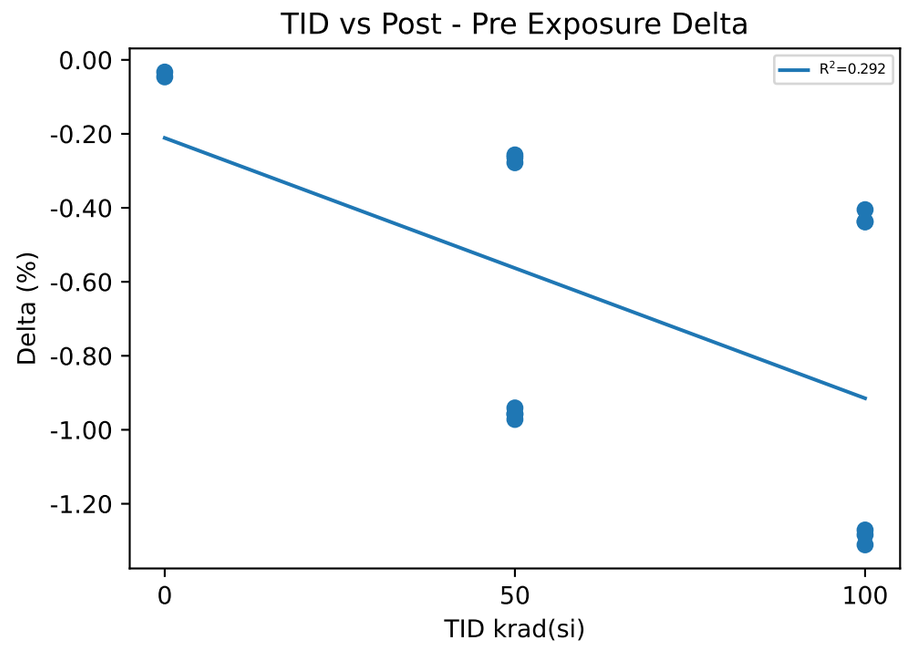
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	10.067	9.107	-0.96
89	50	Biased	10.125	9.15	-0.975
90	50	Biased	10.143	9.192	-0.951
92	50	Biased	10.182	9.22	-0.962
93	50	Unbiased	10.104	9.835	-0.269
94	50	Unbiased	10.223	9.937	-0.286
95	50	Unbiased	10.113	9.847	-0.266
96	100	Biased	10.258	8.943	-1.315
97	100	Biased	10.1	8.819	-1.281
98	100	Biased	10.044	8.754	-1.29
99	100	Unbiased	10.235	9.792	-0.443
100	100	Unbiased	10.157	9.72	-0.437
101	100	Unbiased	10.133	9.724	-0.409
102	0	Correlation	9.985	9.948	-0.037
103	0	Correlation	10.014	9.966	-0.048

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.985	9.9995	10.014	0.020506	9.948	9.957	9.966	0.012728	-0.048	-0.0425	-0.037	0.0077782
50	10.067	10.137	10.223	0.051906	9.107	9.4697	9.937	0.38022	-0.975	-0.667	-0.266	0.36805
100	10.044	10.155	10.258	0.081045	8.754	9.292	9.792	0.50096	-1.315	-0.8625	-0.409	0.47441

Device Test: 6.118 VOL_PWRGD_10MA(VOL_10mA_PWRGD/PWRGD/1.6/3/0/0/10/@VOL_PWRGD_10MA)





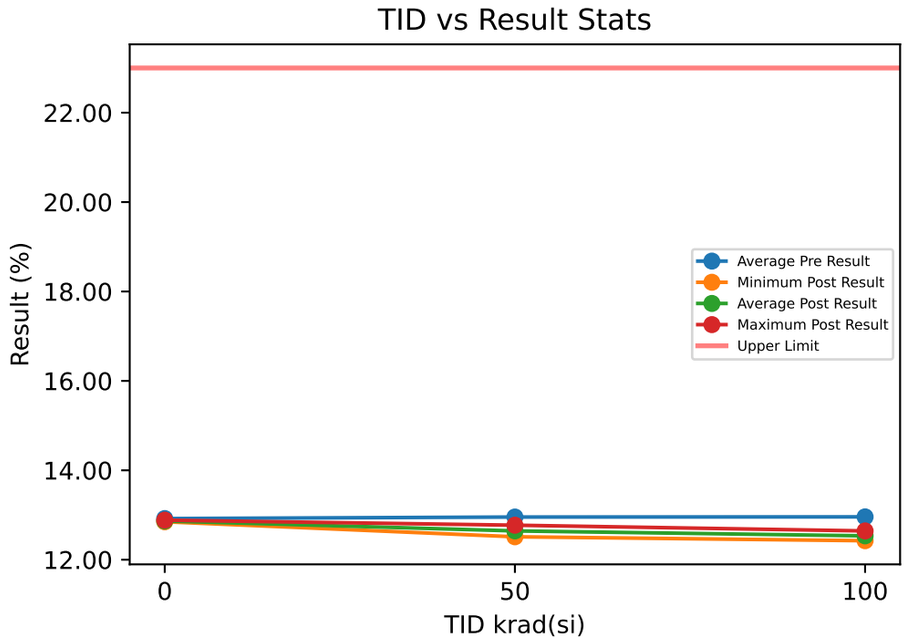
Test Results (Upper Limit = 23.0 (%))

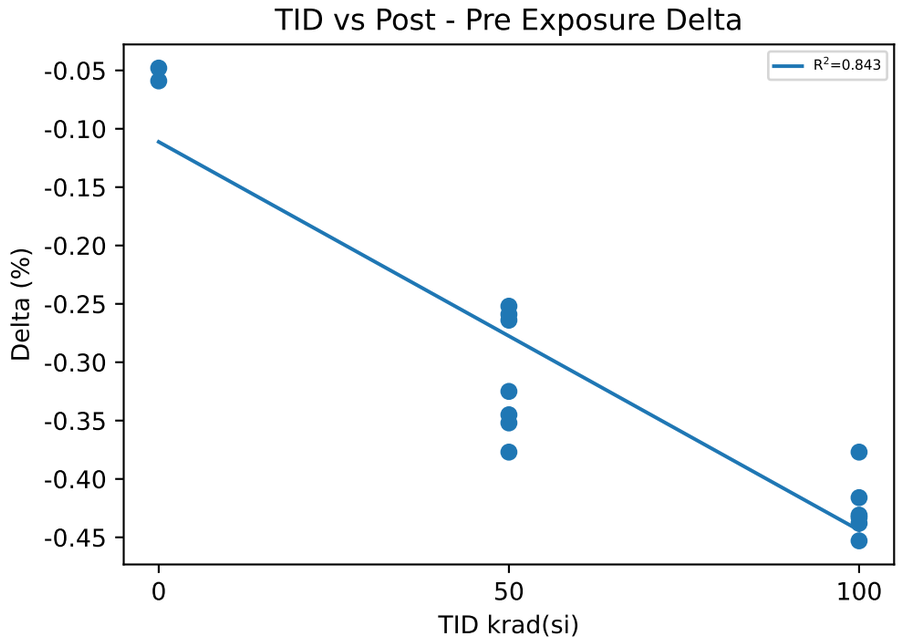
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	10.105	9.147	-0.958
89	50	Biased	10.134	9.162	-0.972
90	50	Biased	10.15	9.209	-0.941
92	50	Biased	10.26	9.303	-0.957
93	50	Unbiased	10.148	9.884	-0.264
94	50	Unbiased	10.211	9.933	-0.278
95	50	Unbiased	10.148	9.891	-0.257
96	100	Biased	10.305	8.994	-1.311
97	100	Biased	10.139	8.868	-1.271
98	100	Biased	10.104	8.82	-1.284
99	100	Unbiased	10.253	9.816	-0.437
100	100	Unbiased	10.259	9.821	-0.438
101	100	Unbiased	10.182	9.777	-0.405
102	0	Correlation	10.042	10.009	-0.033
103	0	Correlation	10.053	10.007	-0.046

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.042	10.047	10.053	0.0077782	10.007	10.008	10.009	0.0014142	-0.046	-0.0395	-0.033	0.0091924
50	10.105	10.165	10.26	0.052448	9.147	9.5041	9.933	0.3764	-0.972	-0.661	-0.257	0.36934
100	10.104	10.207	10.305	0.077823	8.82	9.3493	9.821	0.50225	-1.311	-0.85767	-0.405	0.47246

Device Test: 6.119 VOL_RESET_10MA(VOL_10mA_RESETB1/RESETB1/1.6/14/0/0/10/@VOL_RESET_10MA)





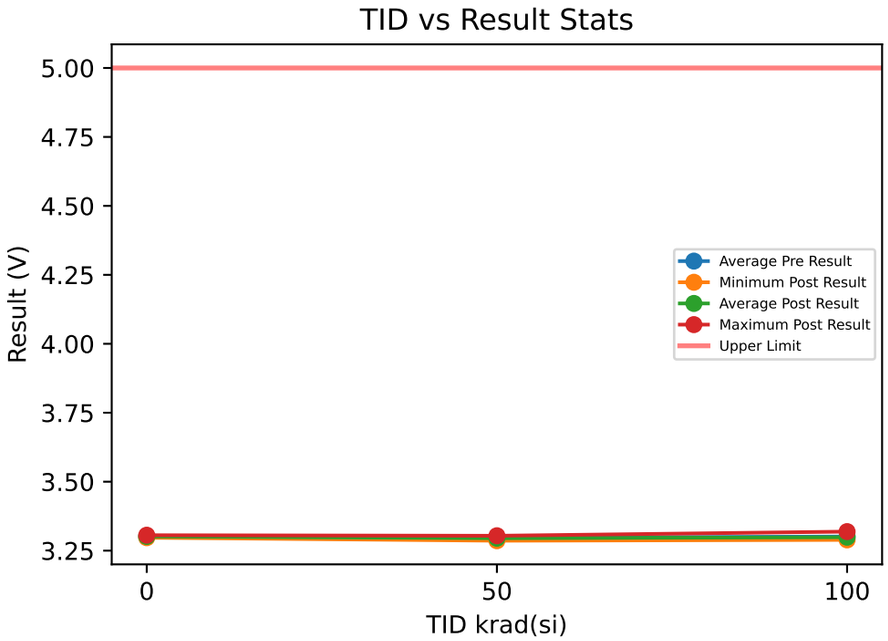
Test Results (Upper Limit = 23.0 (%))

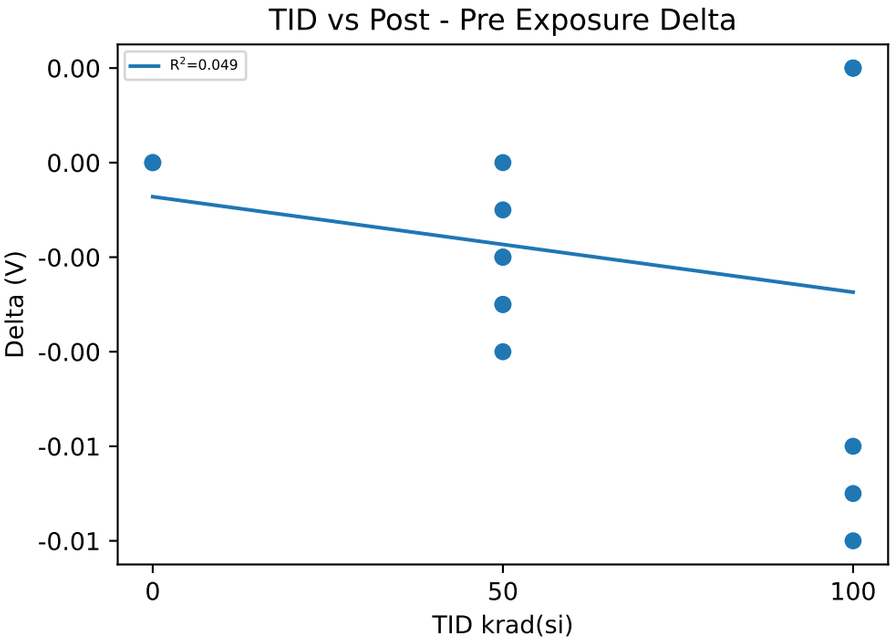
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.89	12.513	-0.377
89	50	Biased	12.951	12.606	-0.345
90	50	Biased	13.011	12.659	-0.352
92	50	Biased	12.879	12.554	-0.325
93	50	Unbiased	12.964	12.712	-0.252
94	50	Unbiased	13.036	12.772	-0.264
95	50	Unbiased	12.953	12.694	-0.259
96	100	Biased	13.016	12.585	-0.431
97	100	Biased	12.884	12.446	-0.438
98	100	Biased	12.878	12.425	-0.453
99	100	Unbiased	13.077	12.644	-0.433
100	100	Unbiased	12.94	12.524	-0.416
101	100	Unbiased	12.957	12.58	-0.377
102	0	Correlation	12.897	12.849	-0.048
103	0	Correlation	12.944	12.885	-0.059

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.897	12.921	12.944	0.033234	12.849	12.867	12.885	0.025456	-0.059	-0.0535	-0.048	0.0077782
50	12.879	12.955	13.036	0.057444	12.513	12.644	12.772	0.091686	-0.377	-0.31057	-0.252	0.051286
100	12.878	12.959	13.077	0.077102	12.425	12.534	12.644	0.085489	-0.453	-0.42467	-0.377	0.02622

Device Test: 6.12 VLDO_I_MAX(VLDO_IMAX/VLDO//14/0/0/0/@VLDO_I_IMAX)





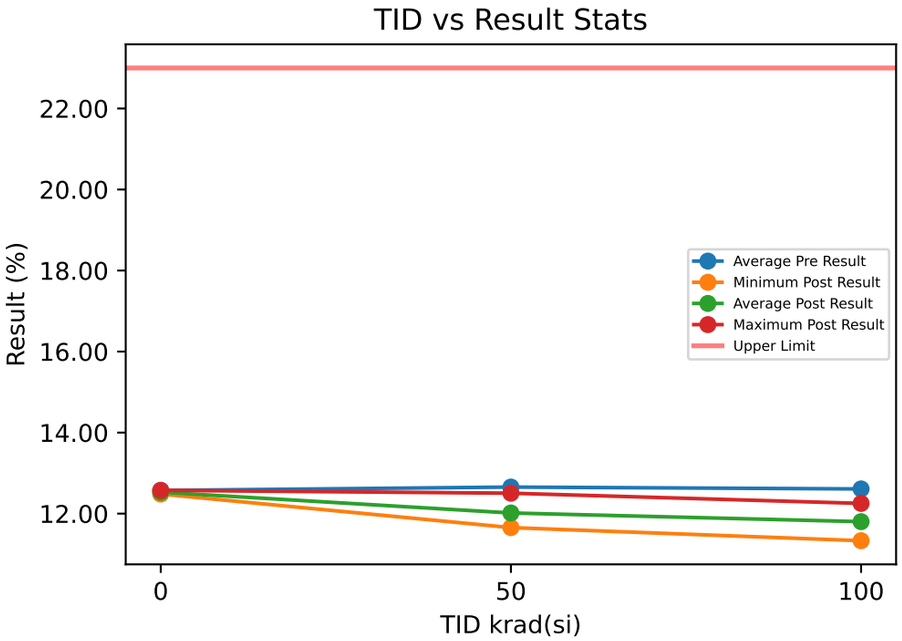
Test Results (Upper Limit = 5.0 (V))

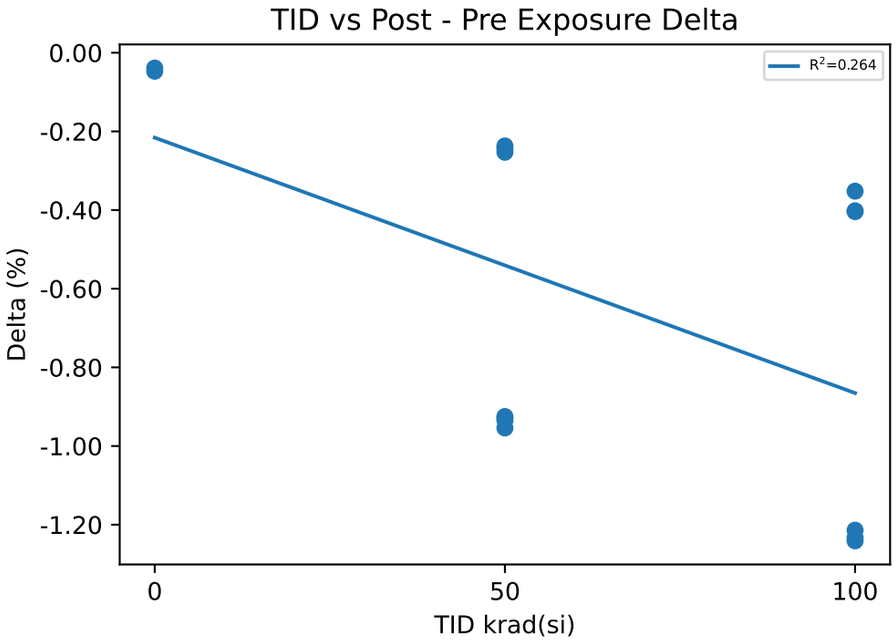
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	3.291	3.291	0
89	50	Biased	3.304	3.301	-0.003
90	50	Biased	3.288	3.286	-0.002
92	50	Biased	3.305	3.303	-0.002
93	50	Unbiased	3.308	3.304	-0.004
94	50	Unbiased	3.29	3.289	-0.001
95	50	Unbiased	3.294	3.291	-0.003
96	100	Biased	3.303	3.295	-0.008
97	100	Biased	3.302	3.296	-0.006
98	100	Biased	3.317	3.319	0.002
99	100	Unbiased	3.296	3.298	0.002
100	100	Unbiased	3.293	3.295	0.002
101	100	Unbiased	3.296	3.289	-0.007
102	0	Correlation	3.306	3.306	0
103	0	Correlation	3.297	3.297	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.297	3.3015	3.306	0.006364	3.297	3.3015	3.306	0.006364	0	0	0	0
50	3.288	3.2971	3.308	0.0082549	3.286	3.295	3.304	0.0074162	-0.004	-0.0021429	0	0.0013452
100	3.293	3.3012	3.317	0.0086583	3.289	3.2987	3.319	0.010405	-0.008	-0.0025	0.002	0.0049699

Device Test: 6.120 VOL_RESET_10MA(VOL_10mA_RESETB2/RESETB2/1.6/14/0/0/10/@VOL_RESET_10MA)





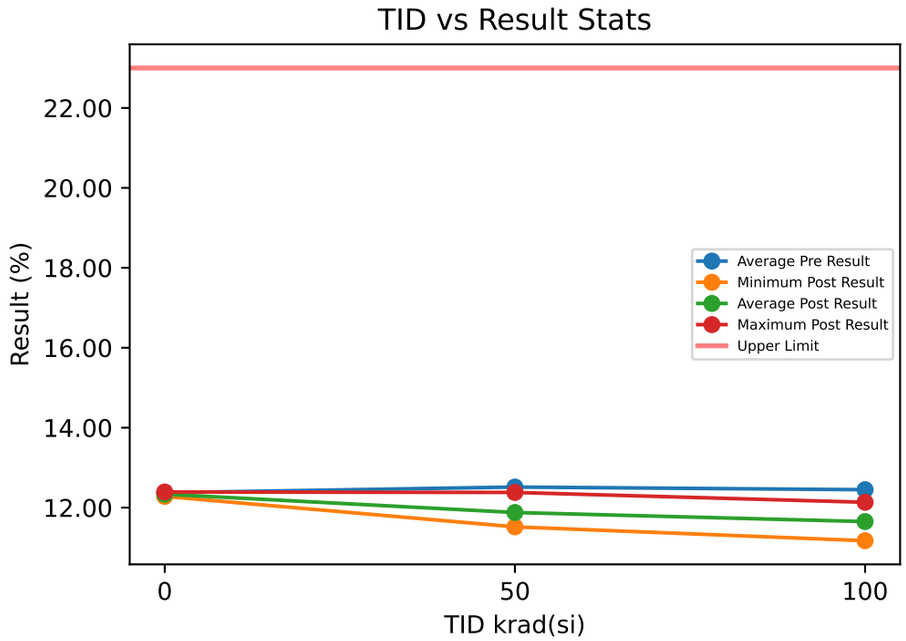
Test Results (Upper Limit = 23.0 (%))

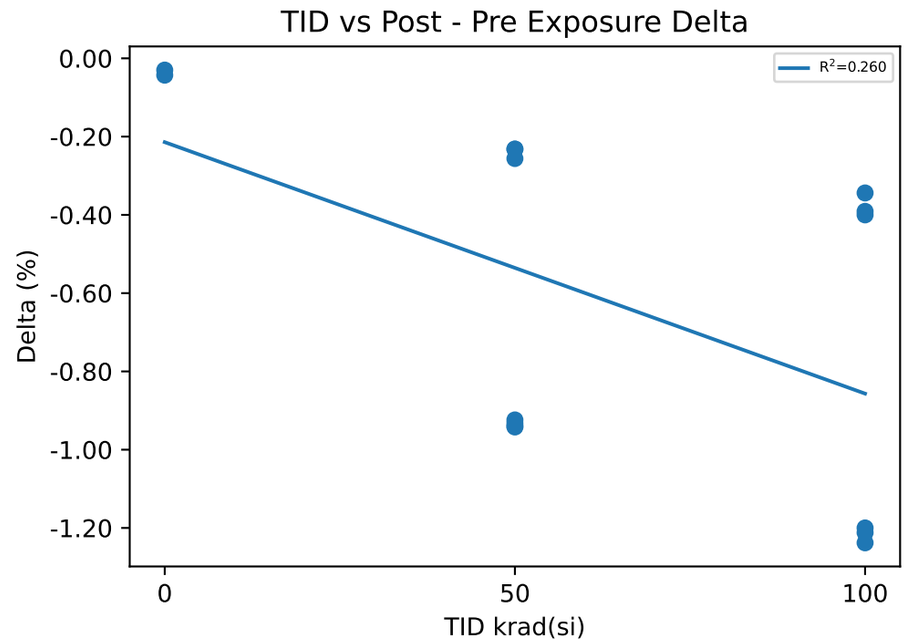
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.609	11.655	-0.954
89	50	Biased	12.638	11.713	-0.925
90	50	Biased	12.638	11.703	-0.935
92	50	Biased	12.775	11.846	-0.929
93	50	Unbiased	12.594	12.357	-0.237
94	50	Unbiased	12.757	12.504	-0.253
95	50	Unbiased	12.575	12.332	-0.243
96	100	Biased	12.615	11.401	-1.214
97	100	Biased	12.623	11.382	-1.241
98	100	Biased	12.564	11.331	-1.233
99	100	Unbiased	12.656	12.252	-0.404
100	100	Unbiased	12.64	12.238	-0.402
101	100	Unbiased	12.557	12.205	-0.352
102	0	Correlation	12.522	12.483	-0.039
103	0	Correlation	12.622	12.575	-0.047

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.522	12.572	12.622	0.070711	12.483	12.529	12.575	0.065054	-0.047	-0.043	-0.039	0.0056569
50	12.575	12.655	12.775	0.079182	11.655	12.016	12.504	0.3659	-0.954	-0.63943	-0.237	0.36972
100	12.557	12.609	12.656	0.040326	11.331	11.801	12.252	0.47203	-1.241	-0.80767	-0.352	0.46237

Device Test: 6.121 VOL_RESET_10MA(VOL_10mA_RESETB3/RESETB3/1.6/14/0/0/10/@VOL_RESET_10MA)





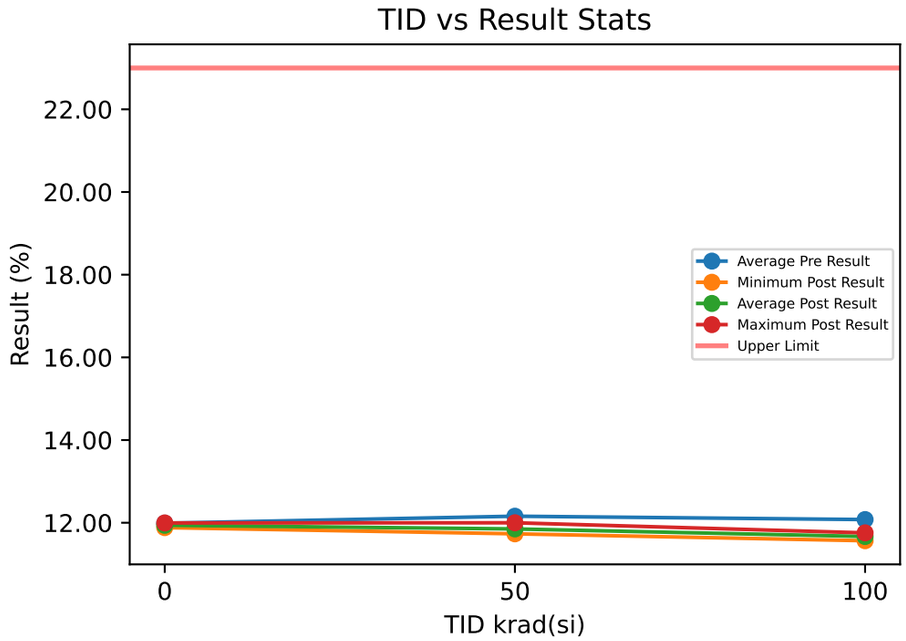
Test Results (Upper Limit = 23.0 (%))

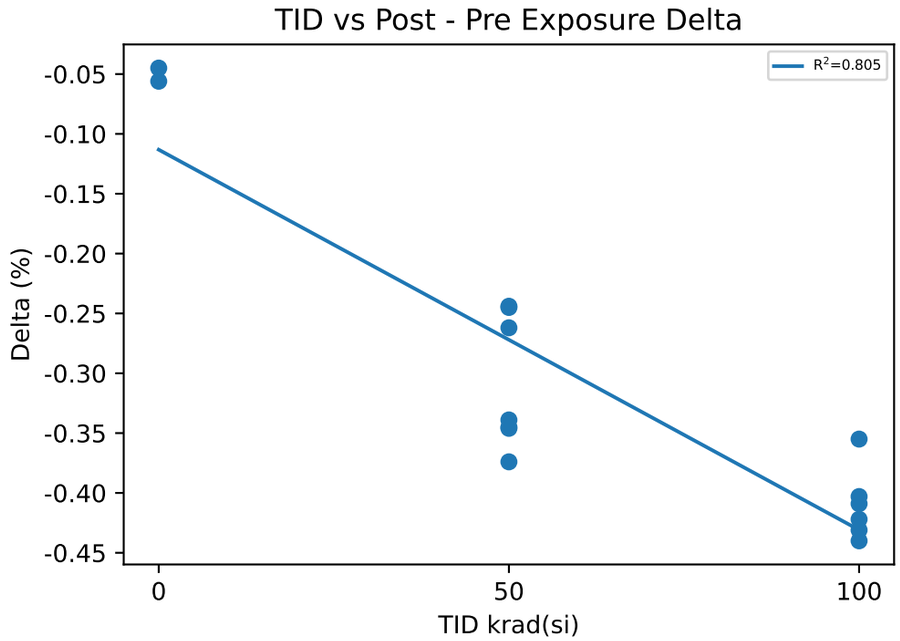
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.459	11.519	-0.94
89	50	Biased	12.523	11.59	-0.933
90	50	Biased	12.507	11.583	-0.924
92	50	Biased	12.634	11.692	-0.942
93	50	Unbiased	12.444	12.212	-0.232
94	50	Unbiased	12.636	12.38	-0.256
95	50	Unbiased	12.402	12.17	-0.232
96	100	Biased	12.488	11.288	-1.2
97	100	Biased	12.424	11.212	-1.212
98	100	Biased	12.41	11.172	-1.238
99	100	Unbiased	12.534	12.134	-0.4
100	100	Unbiased	12.429	12.038	-0.391
101	100	Unbiased	12.405	12.061	-0.344
102	0	Correlation	12.311	12.281	-0.03
103	0	Correlation	12.434	12.391	-0.043

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.311	12.372	12.434	0.086974	12.281	12.336	12.391	0.077782	-0.043	-0.0365	-0.03	0.0091924
50	12.402	12.515	12.636	0.091174	11.519	11.878	12.38	0.36108	-0.942	-0.637	-0.232	0.37149
100	12.405	12.448	12.534	0.05143	11.172	11.651	12.134	0.47013	-1.238	-0.7975	-0.344	0.45973

Device Test: 6.122 VOL_RESET_10MA(VOL_10mA_RESETB4/RESETB4/1.6/14/0/0/10/@VOL_RESET_10MA)





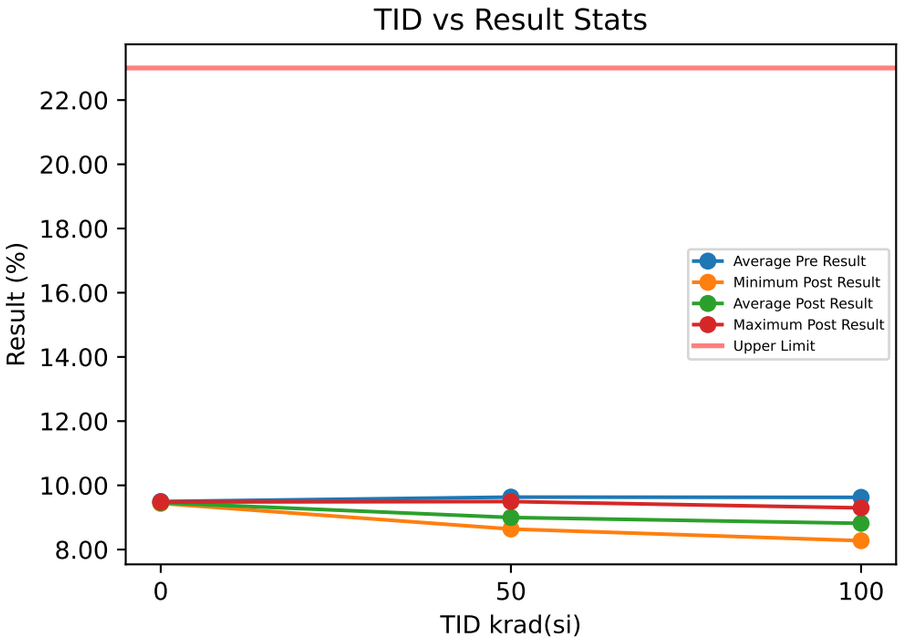
Test Results (Upper Limit = 23.0 (%))

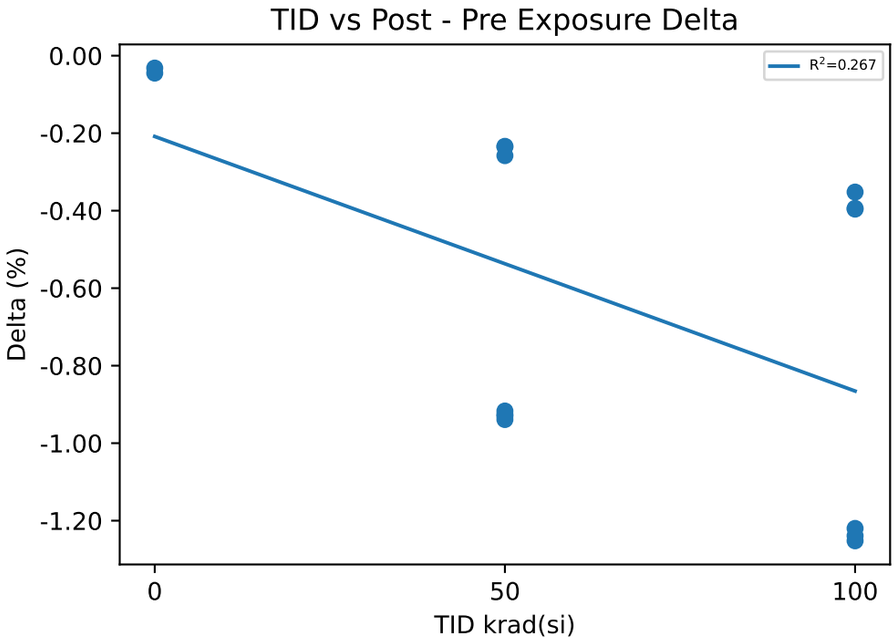
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	12.106	11.732	-0.374
89	50	Biased	12.13	11.784	-0.346
90	50	Biased	12.164	11.819	-0.345
92	50	Biased	12.331	11.992	-0.339
93	50	Unbiased	12.081	11.837	-0.244
94	50	Unbiased	12.261	11.999	-0.262
95	50	Unbiased	12.033	11.788	-0.245
96	100	Biased	12.158	11.736	-0.422
97	100	Biased	12.064	11.633	-0.431
98	100	Biased	12.005	11.565	-0.44
99	100	Unbiased	12.164	11.755	-0.409
100	100	Unbiased	12.053	11.65	-0.403
101	100	Unbiased	12.018	11.663	-0.355
102	0	Correlation	11.927	11.882	-0.045
103	0	Correlation	12.051	11.995	-0.056

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.927	11.989	12.051	0.087681	11.882	11.938	11.995	0.079903	-0.056	-0.0505	-0.045	0.0077782
50	12.033	12.158	12.331	0.10458	11.732	11.85	11.999	0.10458	-0.374	-0.30786	-0.244	0.055243
100	12.005	12.077	12.164	0.068615	11.565	11.667	11.755	0.069814	-0.44	-0.41	-0.355	0.030199

Device Test: 6.123 VOL_WDO_10MA(VOL_10mA_WDOB/WDOB/1.6/14/0/0/10/@VOL_WDO_10MA)





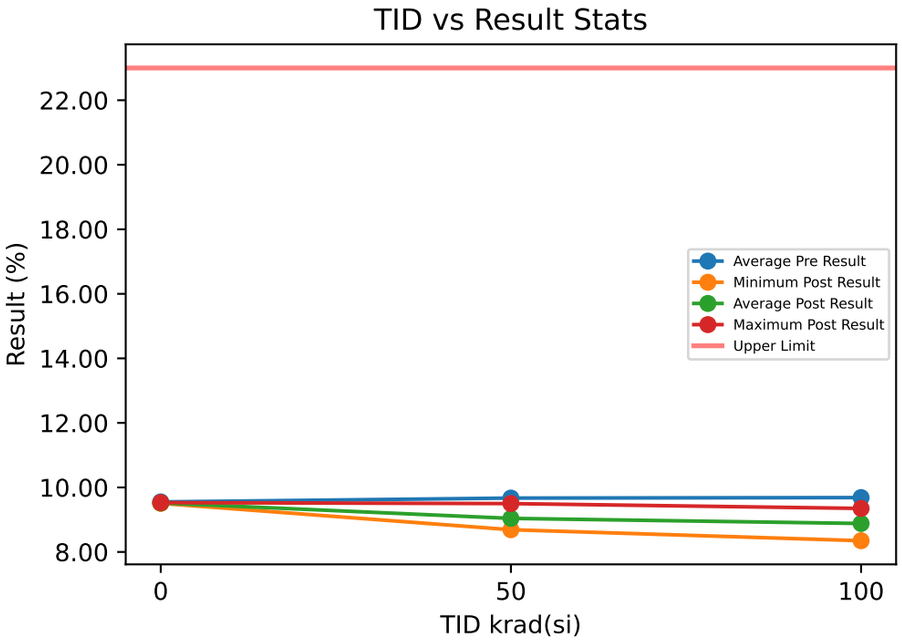
Test Results (Upper Limit = 23.0 (%))

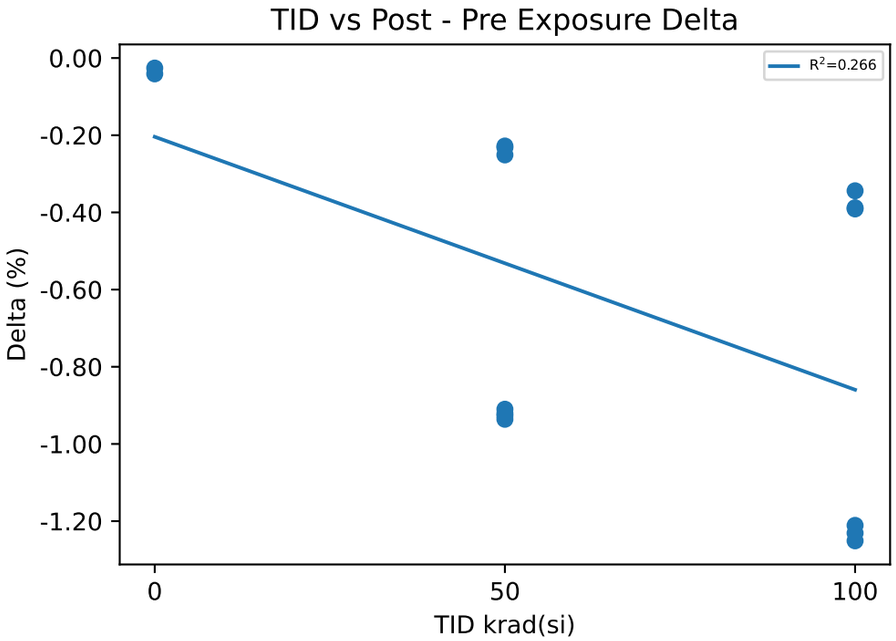
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	9.569	8.639	-0.93
89	50	Biased	9.622	8.683	-0.939
90	50	Biased	9.642	8.725	-0.917
92	50	Biased	9.672	8.746	-0.926
93	50	Unbiased	9.576	9.341	-0.235
94	50	Unbiased	9.753	9.495	-0.258
95	50	Unbiased	9.598	9.364	-0.234
96	100	Biased	9.731	8.479	-1.252
97	100	Biased	9.572	8.352	-1.22
98	100	Biased	9.514	8.275	-1.239
99	100	Unbiased	9.694	9.298	-0.396
100	100	Unbiased	9.642	9.248	-0.394
101	100	Unbiased	9.602	9.25	-0.352
102	0	Correlation	9.47	9.438	-0.032
103	0	Correlation	9.525	9.48	-0.045

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.47	9.4975	9.525	0.038891	9.438	9.459	9.48	0.029698	-0.045	-0.0385	-0.032	0.0091924
50	9.569	9.6331	9.753	0.064152	8.639	8.999	9.495	0.37964	-0.939	-0.63414	-0.234	0.36664
100	9.514	9.6258	9.731	0.079926	8.275	8.817	9.298	0.49575	-1.252	-0.80883	-0.352	0.46941

Device Test: 6.124 VOL_PWRGD_10MA(VOL_10mA_PWRGD/PWRGD/1.6/14/0/0/10/@VOL_PWRGD_10MA)





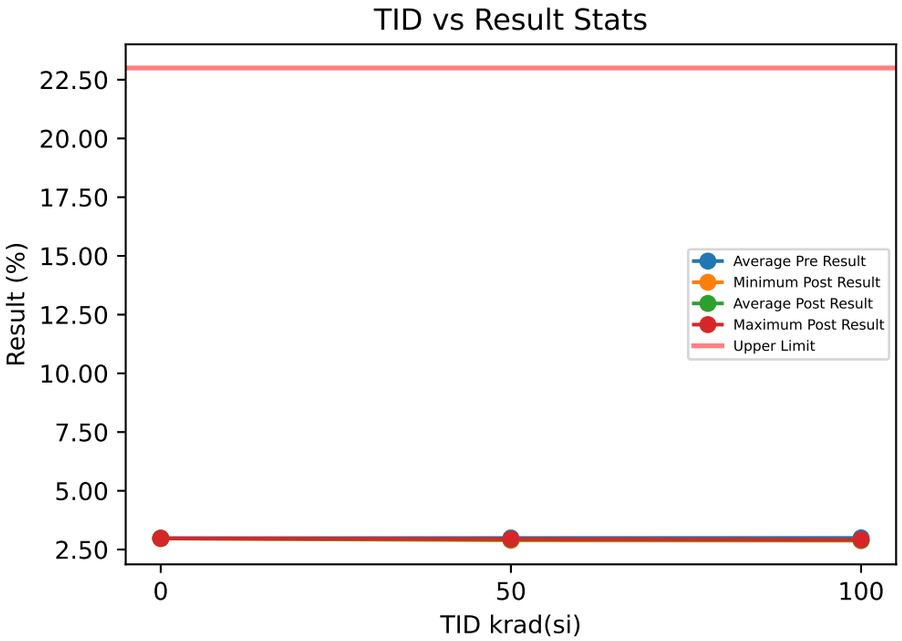
Test Results (Upper Limit = 23.0 (%))

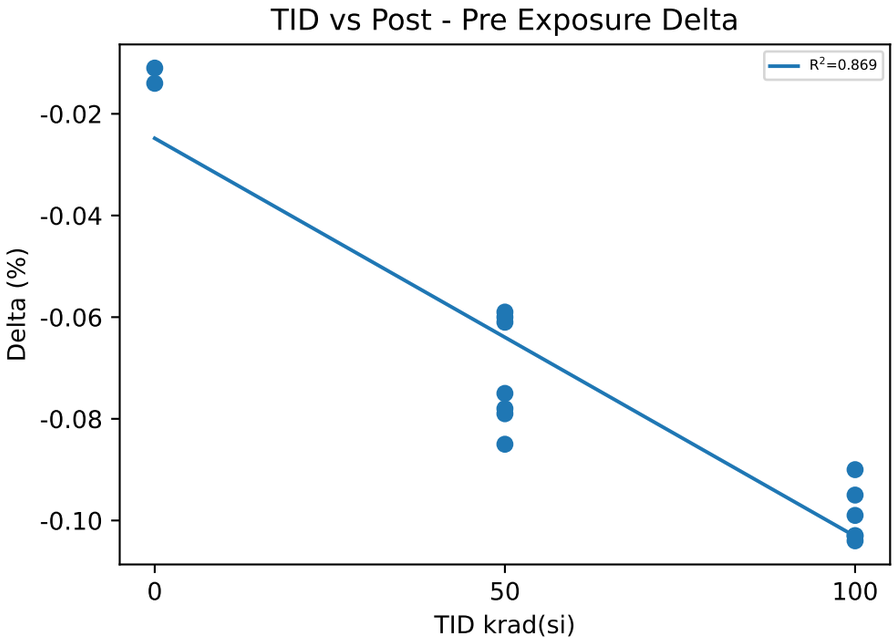
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	9.616	8.689	-0.927
89	50	Biased	9.641	8.705	-0.936
90	50	Biased	9.661	8.751	-0.91
92	50	Biased	9.751	8.83	-0.921
93	50	Unbiased	9.629	9.397	-0.232
94	50	Unbiased	9.75	9.499	-0.251
95	50	Unbiased	9.638	9.41	-0.228
96	100	Biased	9.786	8.535	-1.251
97	100	Biased	9.623	8.412	-1.211
98	100	Biased	9.579	8.348	-1.231
99	100	Unbiased	9.723	9.335	-0.388
100	100	Unbiased	9.74	9.349	-0.391
101	100	Unbiased	9.657	9.313	-0.344
102	0	Correlation	9.532	9.506	-0.026
103	0	Correlation	9.57	9.529	-0.041

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.532	9.551	9.57	0.02687	9.506	9.5175	9.529	0.016263	-0.041	-0.0335	-0.026	0.010607
50	9.616	9.6694	9.751	0.057011	8.689	9.0401	9.499	0.37374	-0.936	-0.62929	-0.228	0.3671
100	9.579	9.6847	9.786	0.078145	8.348	8.882	9.349	0.4971	-1.251	-0.80267	-0.344	0.46968

Device Test: 6.125 VOL_RESET_10MA(VOL_10mA_RESETB1/RESETB1/7/3/0/0/10/@VOL_RESET_10MA)





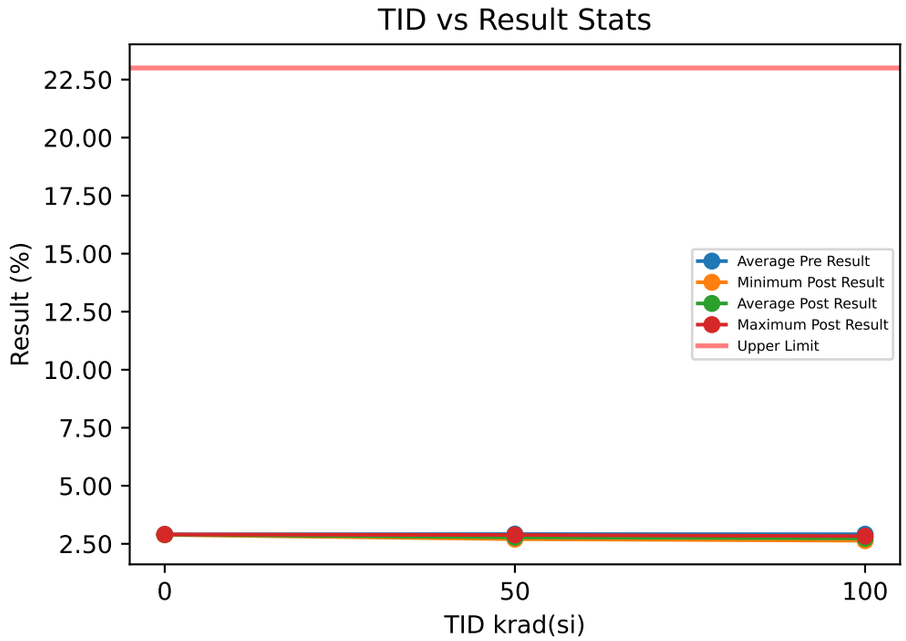
Test Results (Upper Limit = 23.0 (%))

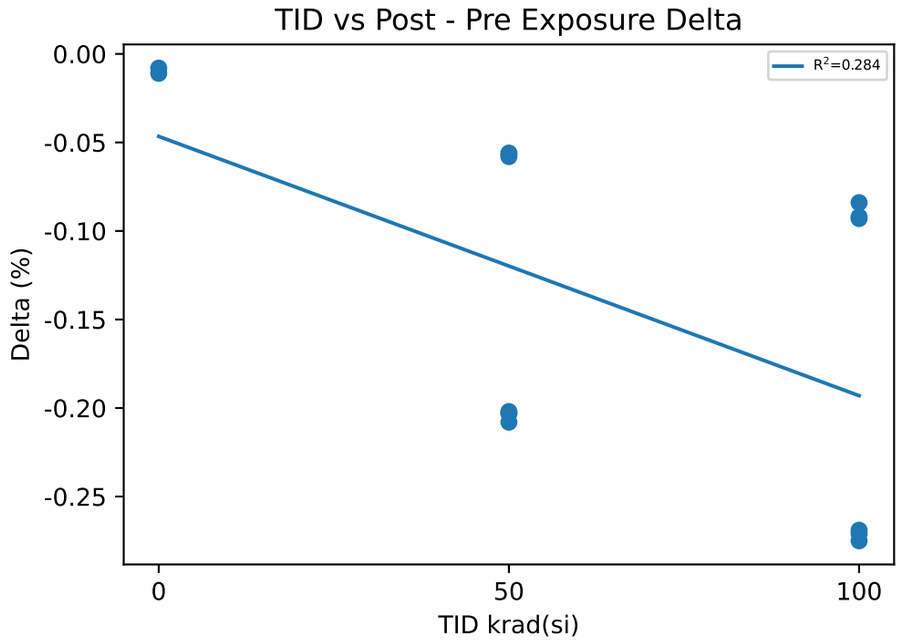
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.974	2.889	-0.085
89	50	Biased	2.992	2.914	-0.078
90	50	Biased	3	2.921	-0.079
92	50	Biased	2.978	2.903	-0.075
93	50	Unbiased	2.998	2.939	-0.059
94	50	Unbiased	3.008	2.947	-0.061
95	50	Unbiased	2.989	2.929	-0.06
96	100	Biased	3.01	2.907	-0.103
97	100	Biased	2.978	2.875	-0.103
98	100	Biased	2.979	2.875	-0.104
99	100	Unbiased	3.021	2.922	-0.099
100	100	Unbiased	2.988	2.893	-0.095
101	100	Unbiased	2.993	2.903	-0.09
102	0	Correlation	2.979	2.968	-0.011
103	0	Correlation	2.989	2.975	-0.014

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.979	2.984	2.989	0.0070711	2.968	2.9715	2.975	0.0049497	-0.014	-0.0125	-0.011	0.0021213
50	2.974	2.9913	3.008	0.01212	2.889	2.9203	2.947	0.020238	-0.085	-0.071	-0.059	0.010724
100	2.978	2.9948	3.021	0.017314	2.875	2.8958	2.922	0.018638	-0.104	-0.099	-0.09	0.0055498

Device Test: 6.126 VOL_RESET_10MA(VOL_10mA_RESETB2/RESETB2/7/3/0/0/10/@VOL_RESET_10MA)





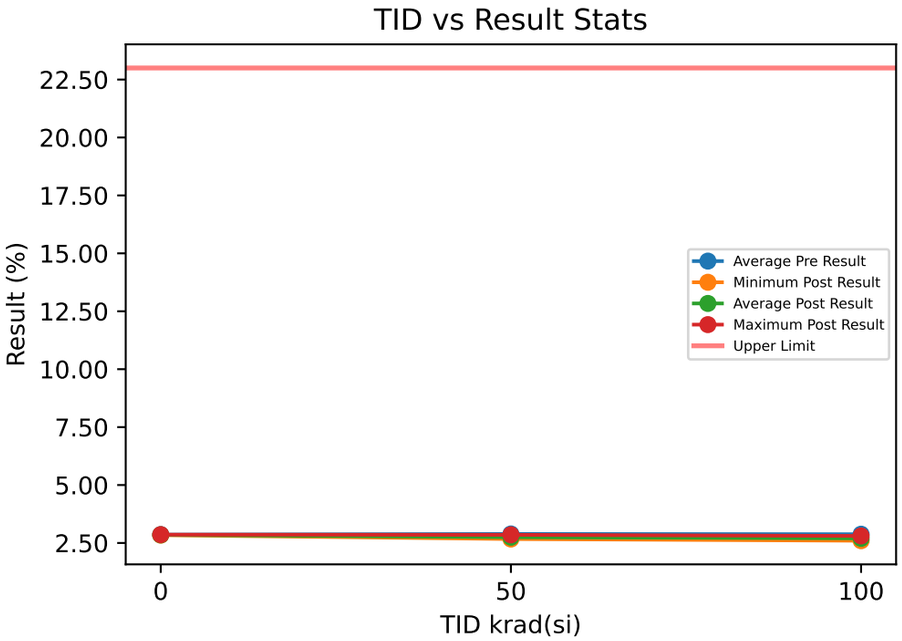
Test Results (Upper Limit = 23.0 (%))

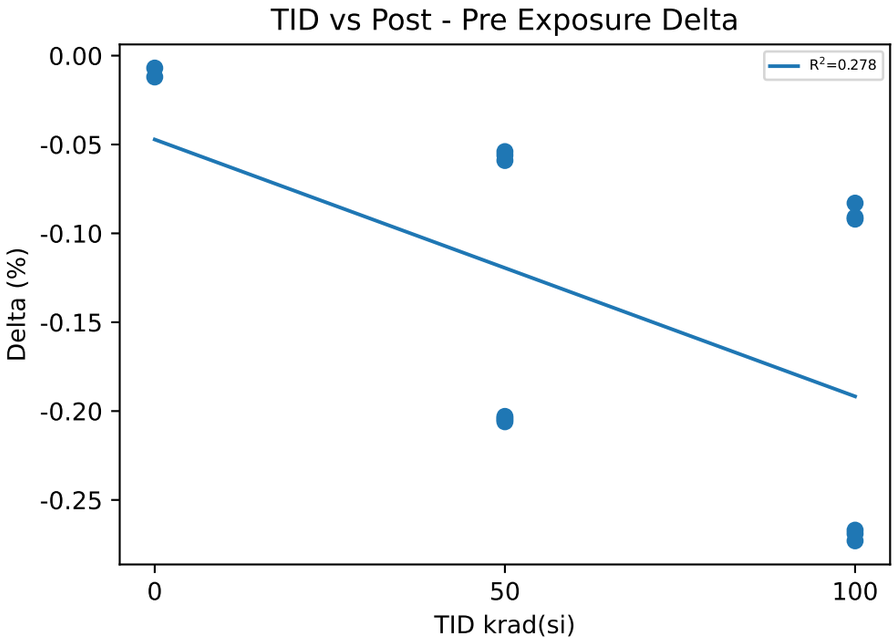
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.907	2.699	-0.208
89	50	Biased	2.916	2.714	-0.202
90	50	Biased	2.912	2.709	-0.203
92	50	Biased	2.947	2.744	-0.203
93	50	Unbiased	2.913	2.857	-0.056
94	50	Unbiased	2.939	2.881	-0.058
95	50	Unbiased	2.904	2.847	-0.057
96	100	Biased	2.916	2.647	-0.269
97	100	Biased	2.918	2.643	-0.275
98	100	Biased	2.904	2.633	-0.271
99	100	Unbiased	2.924	2.831	-0.093
100	100	Unbiased	2.917	2.825	-0.092
101	100	Unbiased	2.9	2.816	-0.084
102	0	Correlation	2.893	2.885	-0.008
103	0	Correlation	2.914	2.903	-0.011

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.893	2.9035	2.914	0.014849	2.885	2.894	2.903	0.012728	-0.011	-0.0095	-0.008	0.0021213
50	2.904	2.9197	2.947	0.01655	2.699	2.7787	2.881	0.079437	-0.208	-0.141	-0.056	0.0786
100	2.9	2.9132	2.924	0.0091742	2.633	2.7325	2.831	0.10045	-0.275	-0.18067	-0.084	0.099753

Device Test: 6.127 VOL_RESET_10MA(VOL_10mA_RESETB3/RESETB3/7/3/0/0/10/@VOL_RESET_10MA)





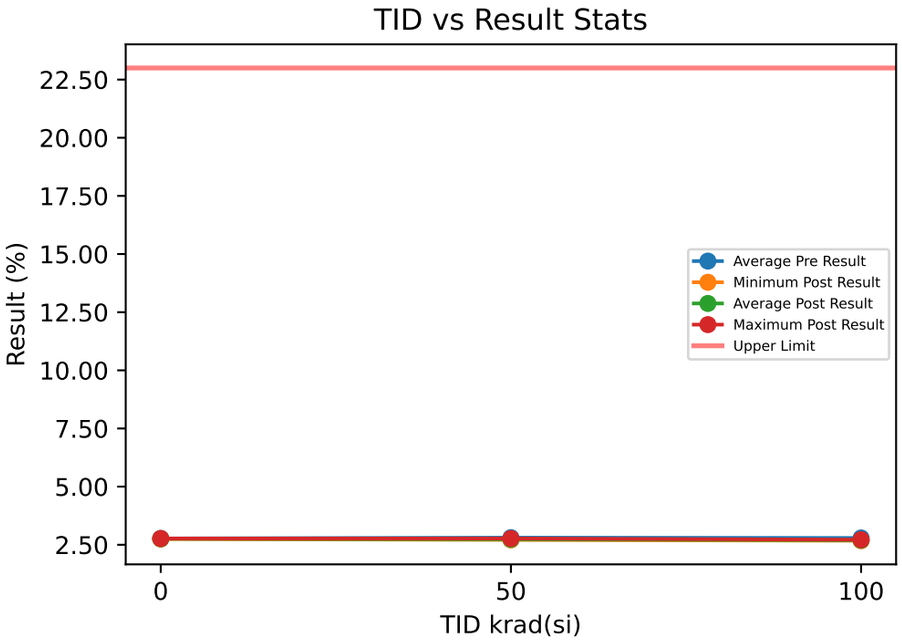
Test Results (Upper Limit = 23.0 (%))

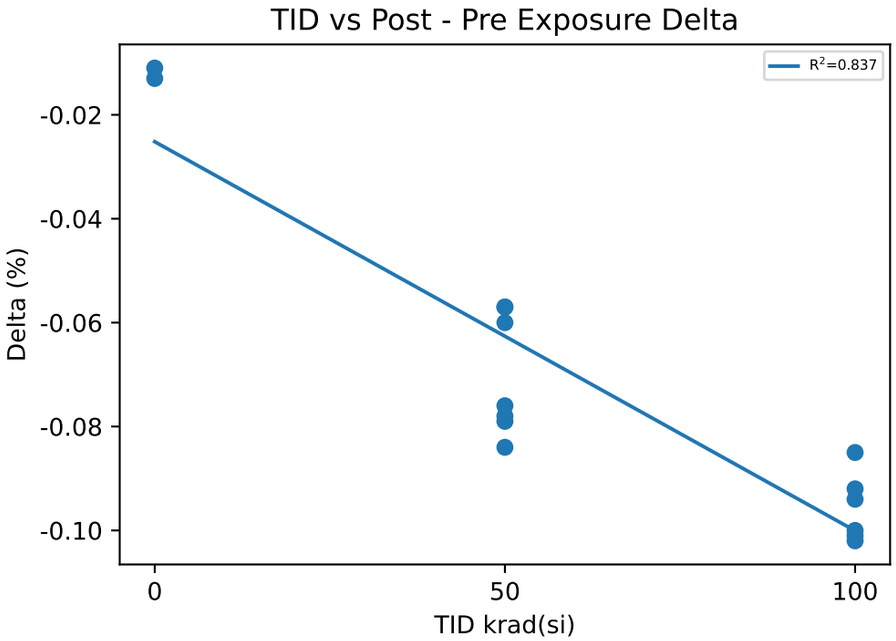
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.876	2.67	-0.206
89	50	Biased	2.889	2.685	-0.204
90	50	Biased	2.883	2.68	-0.203
92	50	Biased	2.915	2.71	-0.205
93	50	Unbiased	2.88	2.824	-0.056
94	50	Unbiased	2.911	2.852	-0.059
95	50	Unbiased	2.865	2.811	-0.054
96	100	Biased	2.888	2.621	-0.267
97	100	Biased	2.874	2.605	-0.269
98	100	Biased	2.87	2.597	-0.273
99	100	Unbiased	2.896	2.804	-0.092
100	100	Unbiased	2.872	2.781	-0.091
101	100	Unbiased	2.868	2.785	-0.083
102	0	Correlation	2.846	2.839	-0.007
103	0	Correlation	2.872	2.86	-0.012

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.846	2.859	2.872	0.018385	2.839	2.8495	2.86	0.014849	-0.012	-0.0095	-0.007	0.0035355
50	2.865	2.8884	2.915	0.018347	2.67	2.7474	2.852	0.078188	-0.206	-0.141	-0.054	0.079217
100	2.868	2.878	2.896	0.011314	2.597	2.6988	2.804	0.10047	-0.273	-0.17917	-0.083	0.099206

Device Test: 6.128 VOL_RESET_10MA(VOL_10mA_RESETB4/RESETB4/7/3/0/0/10/@VOL_RESET_10MA)





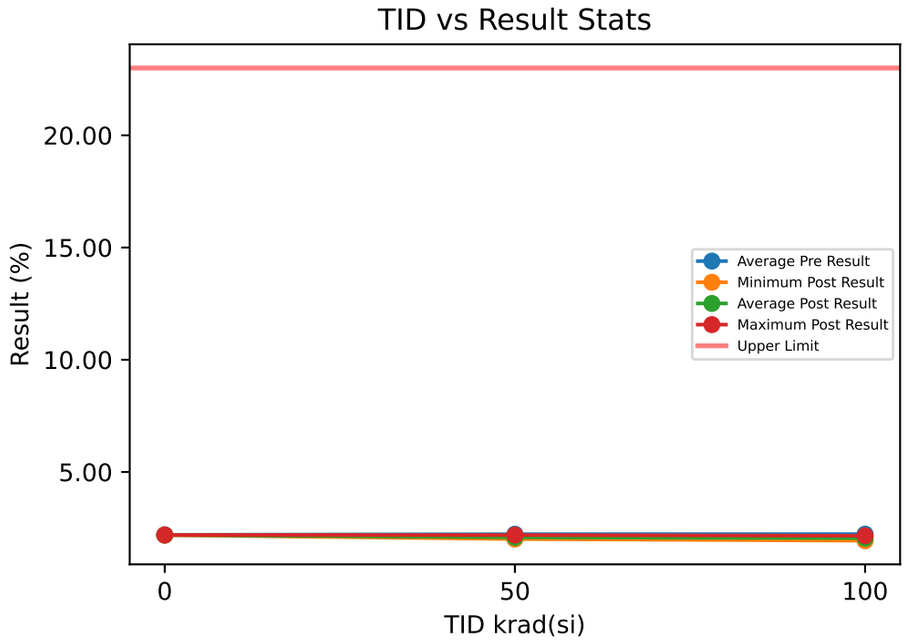
Test Results (Upper Limit = 23.0 (%))

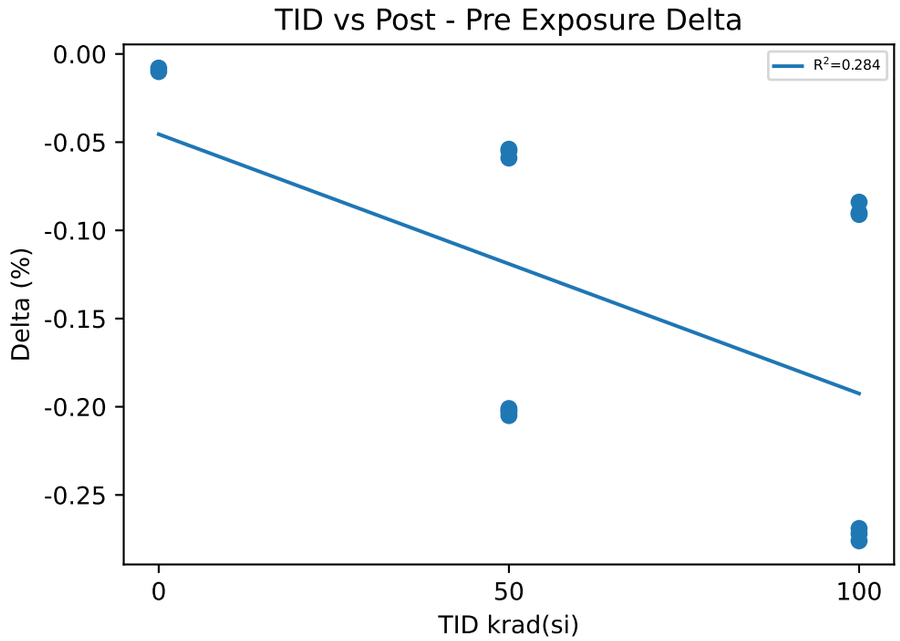
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.793	2.709	-0.084
89	50	Biased	2.798	2.719	-0.079
90	50	Biased	2.804	2.726	-0.078
92	50	Biased	2.845	2.769	-0.076
93	50	Unbiased	2.796	2.739	-0.057
94	50	Unbiased	2.825	2.765	-0.06
95	50	Unbiased	2.779	2.722	-0.057
96	100	Biased	2.811	2.711	-0.1
97	100	Biased	2.791	2.689	-0.102
98	100	Biased	2.775	2.674	-0.101
99	100	Unbiased	2.812	2.718	-0.094
100	100	Unbiased	2.783	2.691	-0.092
101	100	Unbiased	2.778	2.693	-0.085
102	0	Correlation	2.757	2.746	-0.011
103	0	Correlation	2.783	2.77	-0.013

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.757	2.77	2.783	0.018385	2.746	2.758	2.77	0.016971	-0.013	-0.012	-0.011	0.0014142
50	2.779	2.8057	2.845	0.022164	2.709	2.7356	2.769	0.02328	-0.084	-0.070143	-0.057	0.011654
100	2.775	2.7917	2.812	0.016293	2.674	2.696	2.718	0.015975	-0.102	-0.095667	-0.085	0.0065929

Device Test: 6.129 VOL_WDO_10MA(VOL_10mA_WDOB/WDOB/7/3/0/0/10/@VOL_WDO_10MA)





Test Results (Upper Limit = 23.0 (%))

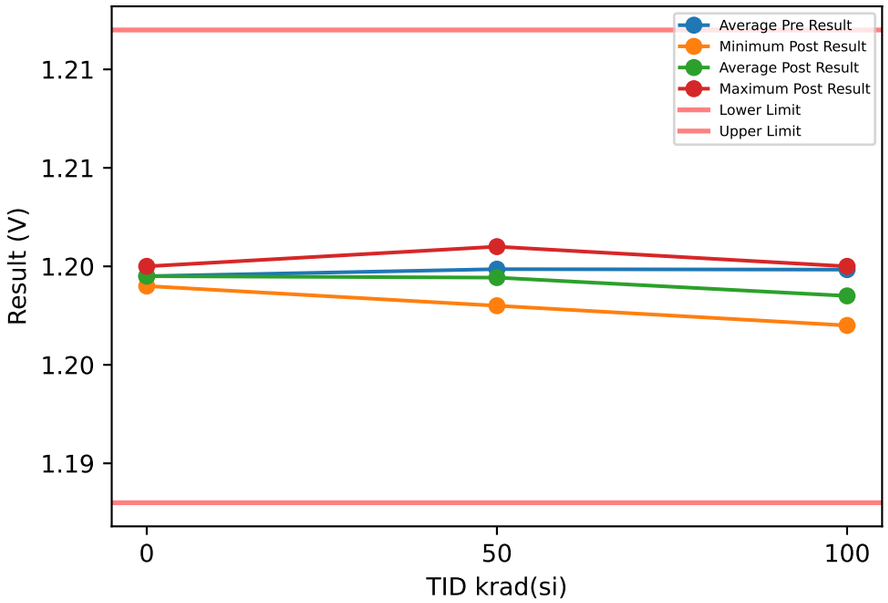
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.213	2.011	-0.202
89	50	Biased	2.225	2.02	-0.205
90	50	Biased	2.23	2.029	-0.201
92	50	Biased	2.239	2.036	-0.203
93	50	Unbiased	2.221	2.166	-0.055
94	50	Unbiased	2.248	2.189	-0.059
95	50	Unbiased	2.222	2.168	-0.054
96	100	Biased	2.254	1.978	-0.276
97	100	Biased	2.218	1.949	-0.269
98	100	Biased	2.209	1.937	-0.272
99	100	Unbiased	2.248	2.157	-0.091
100	100	Unbiased	2.232	2.142	-0.09
101	100	Unbiased	2.226	2.142	-0.084
102	0	Correlation	2.196	2.188	-0.008
103	0	Correlation	2.202	2.192	-0.01

Test Statistics (%)

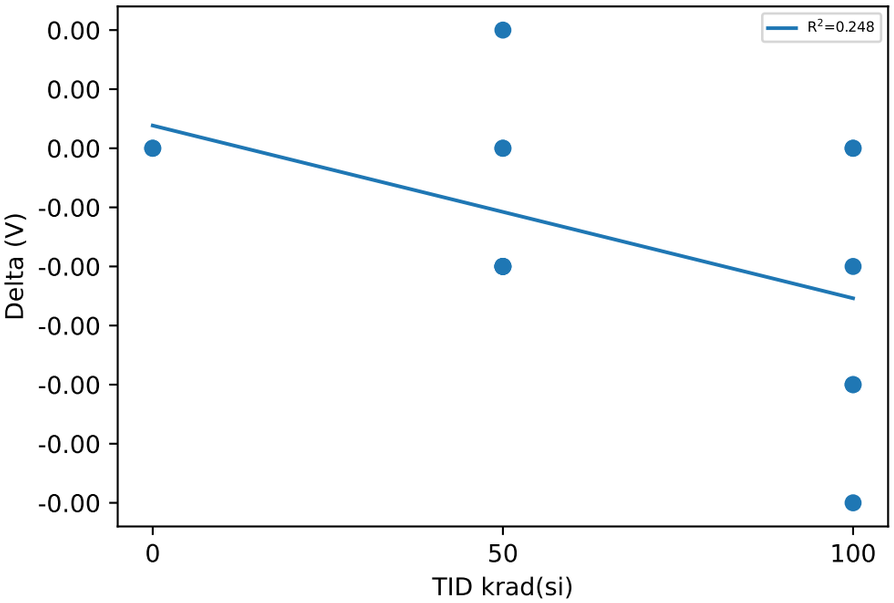
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.196	2.199	2.202	0.0042426	2.188	2.19	2.192	0.0028284	-0.01	-0.009	-0.008	0.0014142
50	2.213	2.2283	2.248	0.011856	2.011	2.0884	2.189	0.081057	-0.205	-0.13986	-0.054	0.078465
100	2.209	2.2312	2.254	0.017302	1.937	2.0508	2.157	0.10633	-0.276	-0.18033	-0.084	0.10083

Device Test: 6.13 REFCAP(REFCAP/REFCAP//3/0/0/0/@REFCAP)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



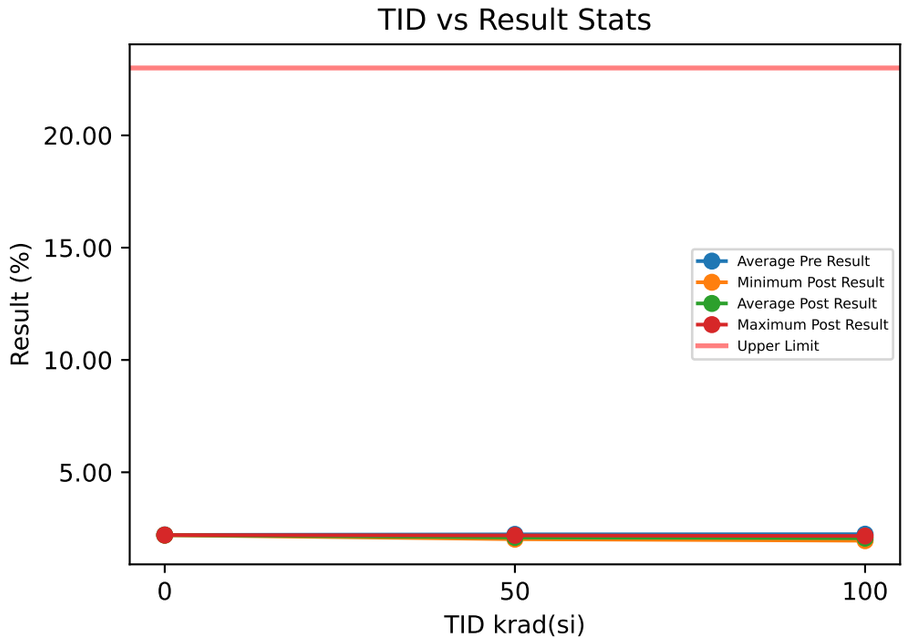
Test Results (Lower Limit = 1.188, Upper Limit = 1.212 (V))

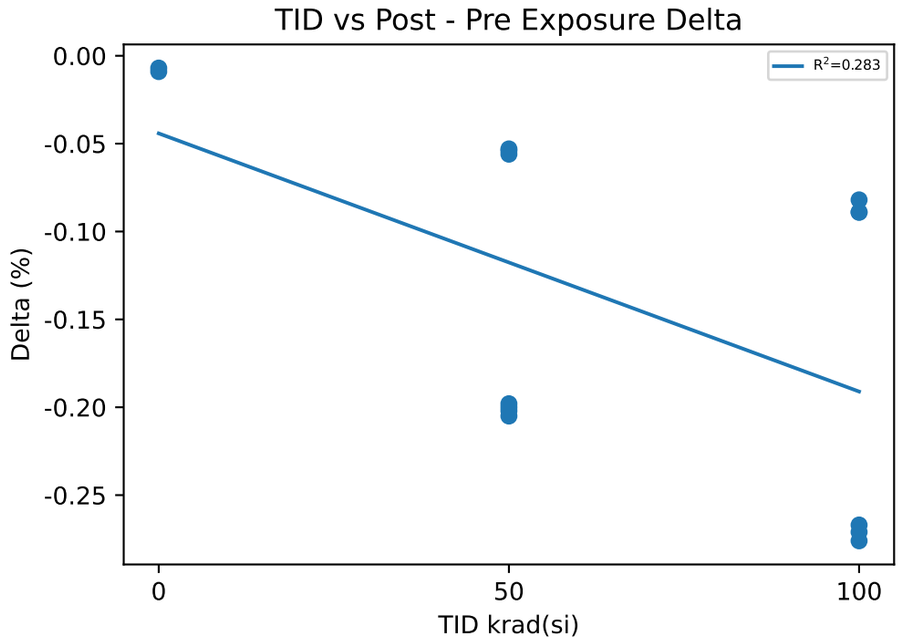
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.199	1.2	0.001
89	50	Biased	1.201	1.2	-0.001
90	50	Biased	1.201	1.201	0
92	50	Biased	1.2	1.199	-0.001
93	50	Unbiased	1.199	1.198	-0.001
94	50	Unbiased	1.2	1.2	0
95	50	Unbiased	1.199	1.198	-0.001
96	100	Biased	1.201	1.198	-0.003
97	100	Biased	1.199	1.197	-0.002
98	100	Biased	1.201	1.2	-0.001
99	100	Unbiased	1.199	1.199	0
100	100	Unbiased	1.199	1.199	0
101	100	Unbiased	1.2	1.198	-0.002
102	0	Correlation	1.199	1.199	0
103	0	Correlation	1.2	1.2	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.199	1.1995	1.2	0.00070711	1.199	1.1995	1.2	0.00070711	0	0	0	0
50	1.199	1.1999	1.201	0.00089974	1.198	1.1994	1.201	0.0011339	-0.001	-0.00042857	0.001	0.0007868
100	1.199	1.1998	1.201	0.00098319	1.197	1.1985	1.2	0.0010488	-0.003	-0.0013333	0	0.0012111

Device Test: 6.130 VOL_PWRGD_10MA(VOL_10mA_PWRGD/PWRGD/7/3/0/0/10/@VOL_PWRGD_10MA)





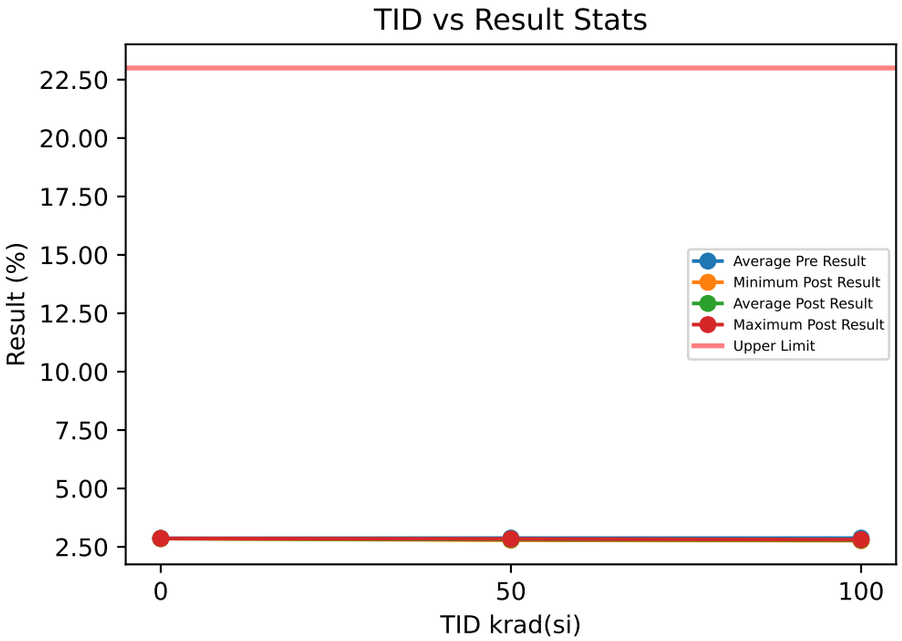
Test Results (Upper Limit = 23.0 (%))

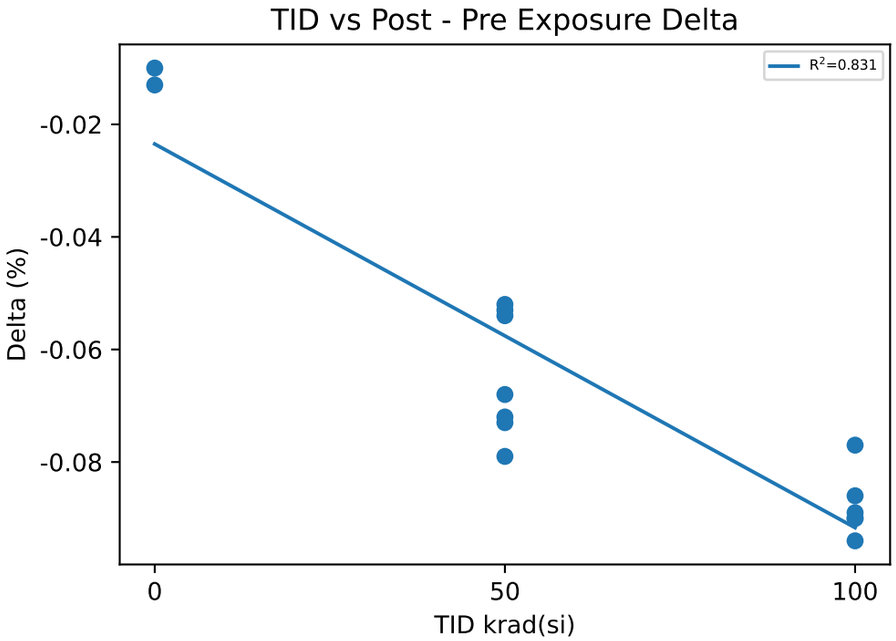
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.223	2.021	-0.202
89	50	Biased	2.231	2.026	-0.205
90	50	Biased	2.234	2.036	-0.198
92	50	Biased	2.255	2.055	-0.2
93	50	Unbiased	2.233	2.179	-0.054
94	50	Unbiased	2.246	2.19	-0.056
95	50	Unbiased	2.232	2.179	-0.053
96	100	Biased	2.267	1.991	-0.276
97	100	Biased	2.23	1.963	-0.267
98	100	Biased	2.224	1.953	-0.271
99	100	Unbiased	2.253	2.164	-0.089
100	100	Unbiased	2.253	2.164	-0.089
101	100	Unbiased	2.238	2.156	-0.082
102	0	Correlation	2.209	2.202	-0.007
103	0	Correlation	2.214	2.205	-0.009

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.209	2.2115	2.214	0.0035355	2.202	2.2035	2.205	0.0021213	-0.009	-0.008	-0.007	0.0014142
50	2.223	2.2363	2.255	0.010673	2.021	2.098	2.19	0.079992	-0.205	-0.13829	-0.053	0.078564
100	2.224	2.2442	2.267	0.016266	1.953	2.0652	2.164	0.10612	-0.276	-0.179	-0.082	0.10122

Device Test: 6.131 VOL_RESET_10MA(VOL_10mA_RESETB1/RESETB1/7/14/0/0/10/@VOL_RESET_10MA)





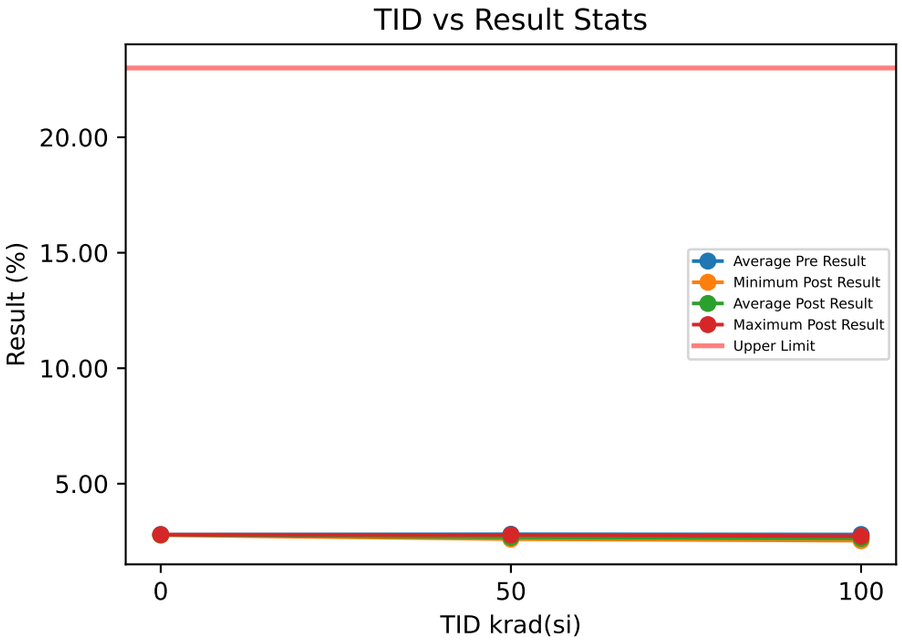
Test Results (Upper Limit = 23.0 (%))

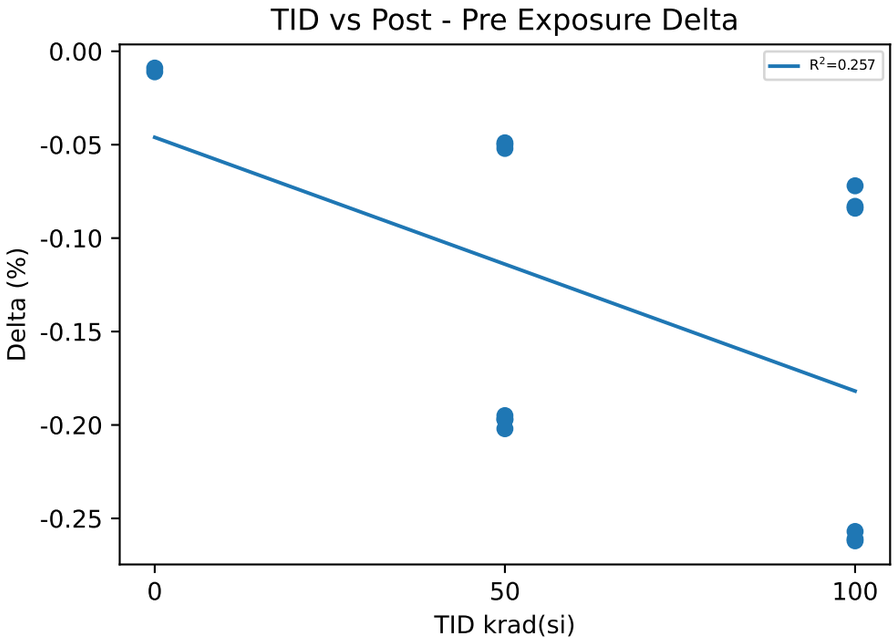
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.862	2.783	-0.079
89	50	Biased	2.877	2.805	-0.072
90	50	Biased	2.889	2.816	-0.073
92	50	Biased	2.861	2.793	-0.068
93	50	Unbiased	2.878	2.826	-0.052
94	50	Unbiased	2.895	2.841	-0.054
95	50	Unbiased	2.875	2.822	-0.053
96	100	Biased	2.89	2.801	-0.089
97	100	Biased	2.86	2.77	-0.09
98	100	Biased	2.858	2.764	-0.094
99	100	Unbiased	2.902	2.812	-0.09
100	100	Unbiased	2.873	2.787	-0.086
101	100	Unbiased	2.875	2.798	-0.077
102	0	Correlation	2.862	2.852	-0.01
103	0	Correlation	2.875	2.862	-0.013

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.862	2.8685	2.875	0.0091924	2.852	2.857	2.862	0.0070711	-0.013	-0.0115	-0.01	0.0021213
50	2.861	2.8767	2.895	0.012606	2.783	2.8123	2.841	0.020014	-0.079	-0.064429	-0.052	0.011178
100	2.858	2.8763	2.902	0.017096	2.764	2.7887	2.812	0.018673	-0.094	-0.087667	-0.077	0.0058195

Device Test: 6.132 VOL_RESET_10MA(VOL_10mA_RESETB2/RESETB2/7/14/0/0/10/@VOL_RESET_10MA)





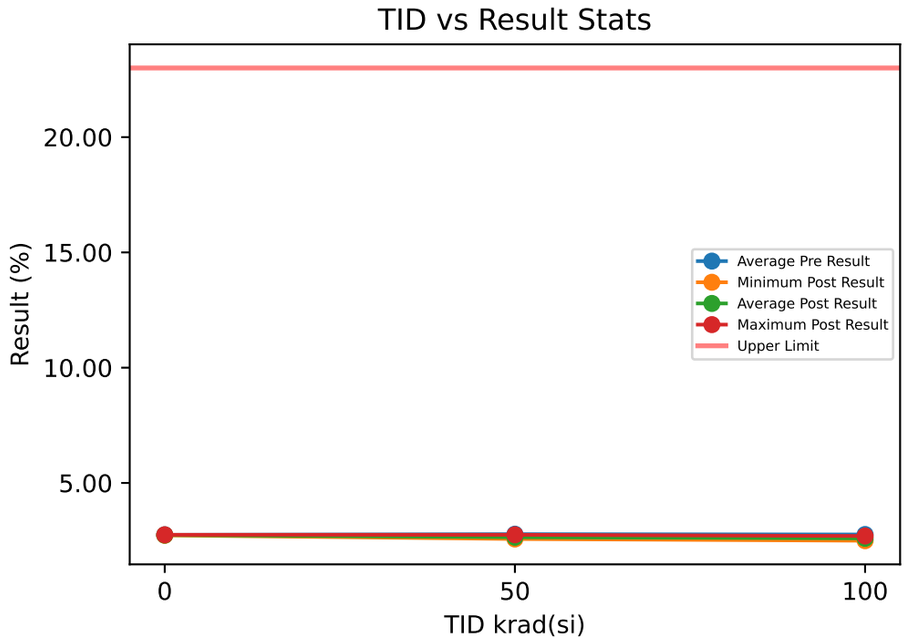
Test Results (Upper Limit = 23.0 (%))

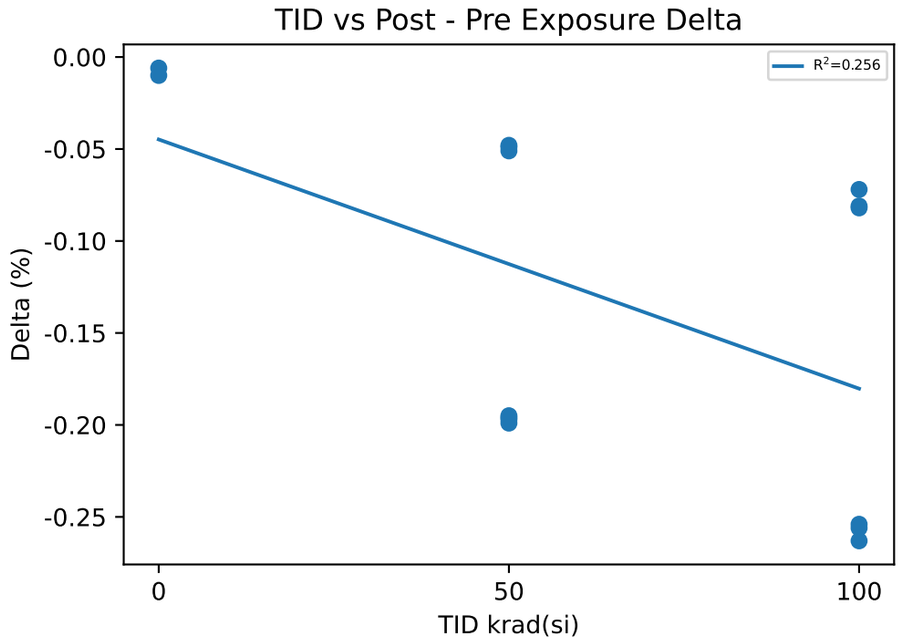
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.801	2.599	-0.202
89	50	Biased	2.809	2.614	-0.195
90	50	Biased	2.808	2.611	-0.197
92	50	Biased	2.838	2.641	-0.197
93	50	Unbiased	2.797	2.748	-0.049
94	50	Unbiased	2.834	2.782	-0.052
95	50	Unbiased	2.794	2.744	-0.05
96	100	Biased	2.805	2.548	-0.257
97	100	Biased	2.802	2.54	-0.262
98	100	Biased	2.792	2.531	-0.261
99	100	Unbiased	2.812	2.728	-0.084
100	100	Unbiased	2.806	2.723	-0.083
101	100	Unbiased	2.789	2.717	-0.072
102	0	Correlation	2.782	2.773	-0.009
103	0	Correlation	2.806	2.795	-0.011

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.782	2.794	2.806	0.016971	2.773	2.784	2.795	0.015556	-0.011	-0.01	-0.009	0.0014142
50	2.794	2.8116	2.838	0.017577	2.599	2.677	2.782	0.077739	-0.202	-0.13457	-0.049	0.078831
100	2.789	2.801	2.812	0.0088091	2.531	2.6312	2.728	0.10044	-0.262	-0.16983	-0.072	0.098877

Device Test: 6.133 VOL_RESET_10MA(VOL_10mA_RESETB3/RESETB3/7/14/0/0/10/@VOL_RESET_10MA)





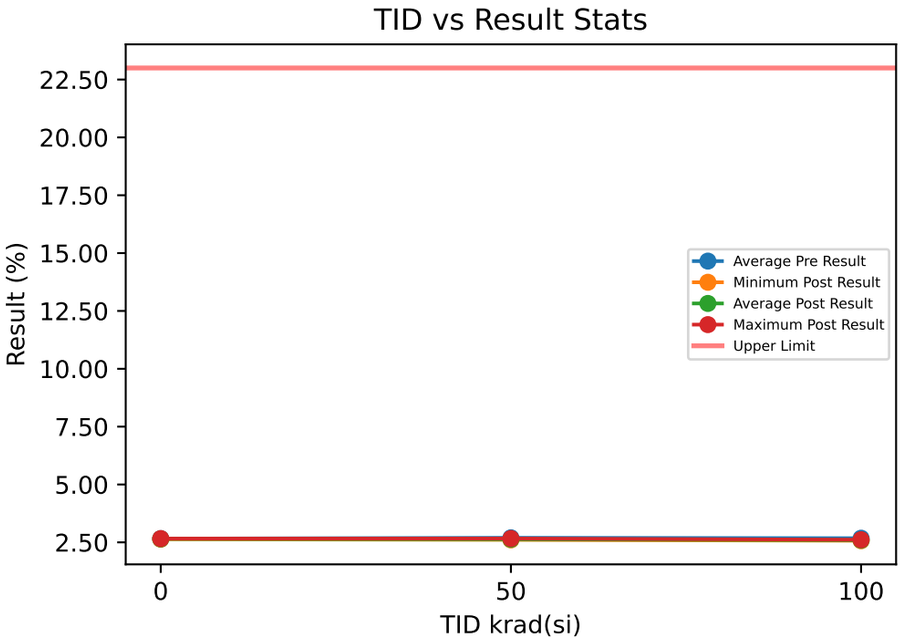
Test Results (Upper Limit = 23.0 (%))

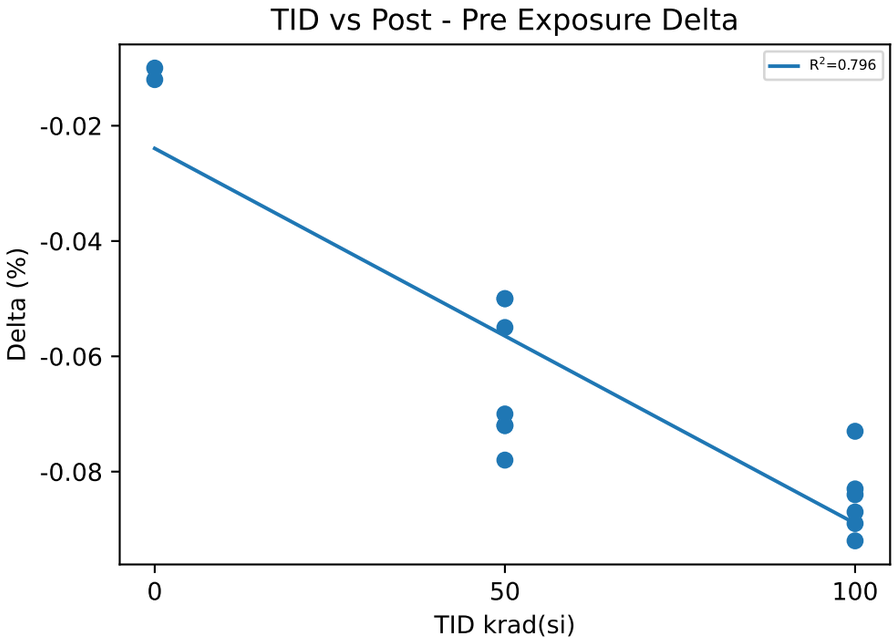
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.768	2.569	-0.199
89	50	Biased	2.78	2.584	-0.196
90	50	Biased	2.777	2.582	-0.195
92	50	Biased	2.803	2.606	-0.197
93	50	Unbiased	2.762	2.714	-0.048
94	50	Unbiased	2.803	2.752	-0.051
95	50	Unbiased	2.755	2.706	-0.049
96	100	Biased	2.775	2.521	-0.254
97	100	Biased	2.757	2.501	-0.256
98	100	Biased	2.757	2.494	-0.263
99	100	Unbiased	2.781	2.699	-0.082
100	100	Unbiased	2.759	2.678	-0.081
101	100	Unbiased	2.755	2.683	-0.072
102	0	Correlation	2.734	2.728	-0.006
103	0	Correlation	2.762	2.752	-0.01

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.734	2.748	2.762	0.019799	2.728	2.74	2.752	0.016971	-0.01	-0.008	-0.006	0.0028284
50	2.755	2.7783	2.803	0.018883	2.569	2.6447	2.752	0.076286	-0.199	-0.13357	-0.048	0.078812
100	2.755	2.764	2.781	0.011082	2.494	2.596	2.699	0.099956	-0.263	-0.168	-0.072	0.098332

Device Test: 6.134 VOL_RESET_10MA(VOL_10mA_RESETB4/RESETB4/7/14/0/0/10/@VOL_RESET_10MA)





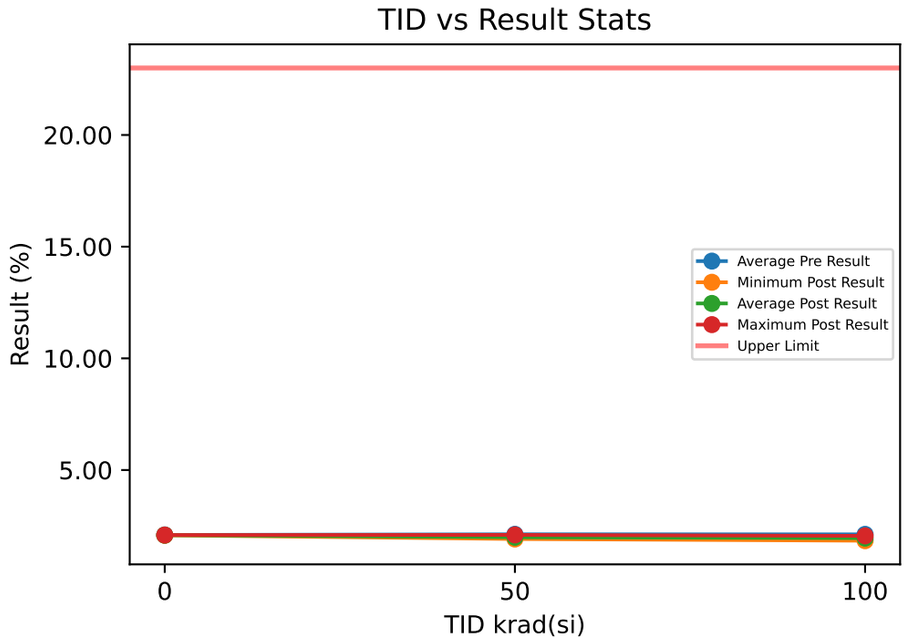
Test Results (Upper Limit = 23.0 (%))

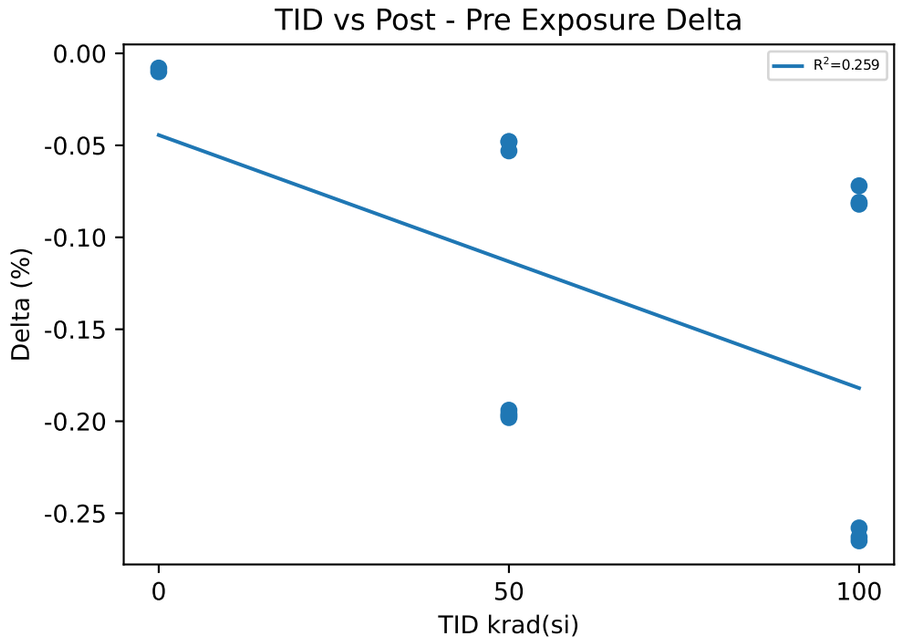
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.685	2.607	-0.078
89	50	Biased	2.69	2.618	-0.072
90	50	Biased	2.698	2.626	-0.072
92	50	Biased	2.733	2.663	-0.07
93	50	Unbiased	2.679	2.629	-0.05
94	50	Unbiased	2.72	2.665	-0.055
95	50	Unbiased	2.668	2.618	-0.05
96	100	Biased	2.698	2.611	-0.087
97	100	Biased	2.674	2.585	-0.089
98	100	Biased	2.662	2.57	-0.092
99	100	Unbiased	2.697	2.613	-0.084
100	100	Unbiased	2.672	2.589	-0.083
101	100	Unbiased	2.665	2.592	-0.073
102	0	Correlation	2.645	2.635	-0.01
103	0	Correlation	2.674	2.662	-0.012

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.645	2.6595	2.674	0.020506	2.635	2.6485	2.662	0.019092	-0.012	-0.011	-0.01	0.0014142
50	2.668	2.6961	2.733	0.023018	2.607	2.6323	2.665	0.022772	-0.078	-0.063857	-0.05	0.011782
100	2.662	2.678	2.698	0.015735	2.57	2.5933	2.613	0.01633	-0.092	-0.084667	-0.073	0.0065929

Device Test: 6.135 VOL_WDO_10MA(VOL_10mA_WDOB/WDOB/7/14/0/0/10/@VOL_WDO_10MA)





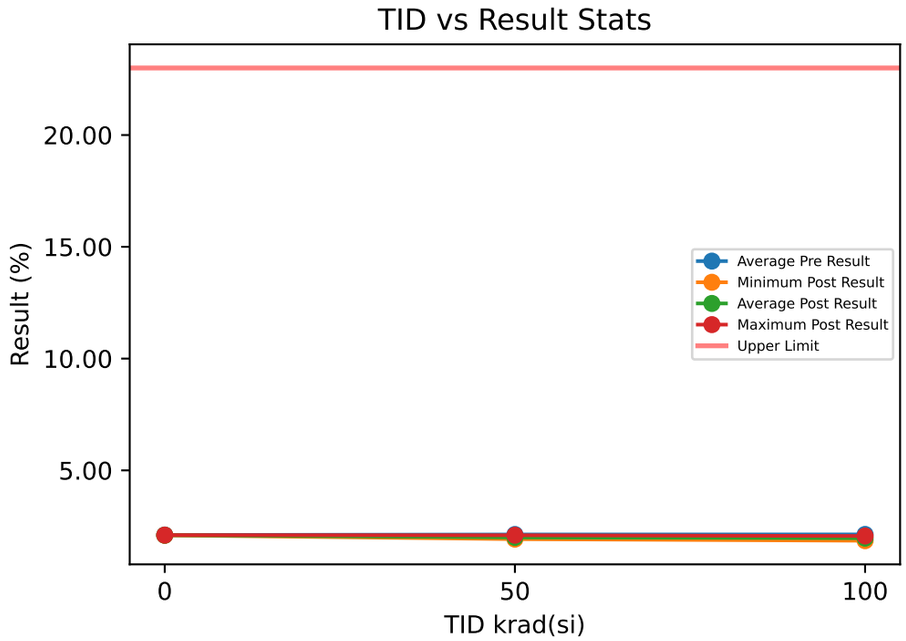
Test Results (Upper Limit = 23.0 (%))

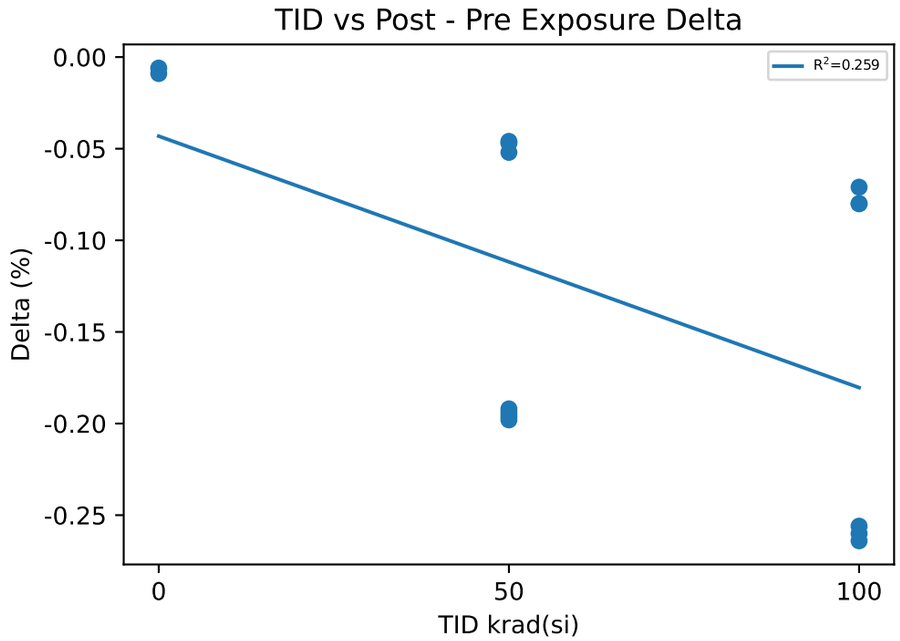
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.109	1.912	-0.197
89	50	Biased	2.12	1.922	-0.198
90	50	Biased	2.125	1.931	-0.194
92	50	Biased	2.132	1.936	-0.196
93	50	Unbiased	2.11	2.062	-0.048
94	50	Unbiased	2.149	2.096	-0.053
95	50	Unbiased	2.114	2.066	-0.048
96	100	Biased	2.144	1.879	-0.265
97	100	Biased	2.108	1.85	-0.258
98	100	Biased	2.098	1.835	-0.263
99	100	Unbiased	2.135	2.053	-0.082
100	100	Unbiased	2.124	2.043	-0.081
101	100	Unbiased	2.115	2.043	-0.072
102	0	Correlation	2.088	2.08	-0.008
103	0	Correlation	2.099	2.089	-0.01

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.088	2.0935	2.099	0.0077782	2.08	2.0845	2.089	0.006364	-0.01	-0.009	-0.008	0.0014142
50	2.109	2.1227	2.149	0.014233	1.912	1.9893	2.096	0.080929	-0.198	-0.13343	-0.048	0.078379
100	2.098	2.1207	2.144	0.017131	1.835	1.9505	2.053	0.10599	-0.265	-0.17017	-0.072	0.10068

Device Test: 6.136 VOL_PWRGD_10MA(VOL_10mA_PWRGD/PWRGD/7/14/0/0/10/@VOL_PWRGD_10MA)





Test Results (Upper Limit = 23.0 (%))

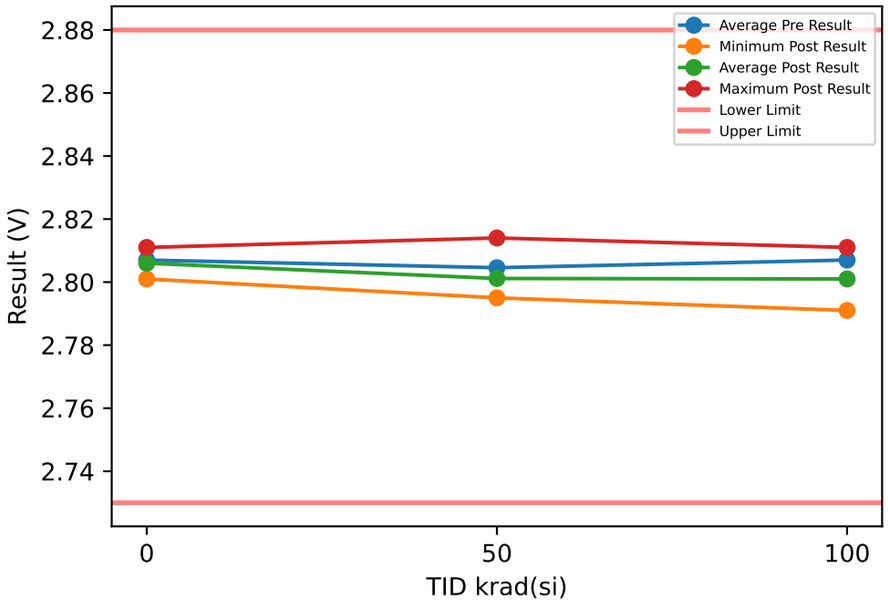
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.12	1.924	-0.196
89	50	Biased	2.127	1.929	-0.198
90	50	Biased	2.131	1.939	-0.192
92	50	Biased	2.149	1.955	-0.194
93	50	Unbiased	2.124	2.077	-0.047
94	50	Unbiased	2.151	2.099	-0.052
95	50	Unbiased	2.124	2.078	-0.046
96	100	Biased	2.158	1.894	-0.264
97	100	Biased	2.122	1.866	-0.256
98	100	Biased	2.113	1.853	-0.26
99	100	Unbiased	2.143	2.063	-0.08
100	100	Unbiased	2.145	2.065	-0.08
101	100	Unbiased	2.129	2.058	-0.071
102	0	Correlation	2.103	2.097	-0.006
103	0	Correlation	2.113	2.104	-0.009

Test Statistics (%)

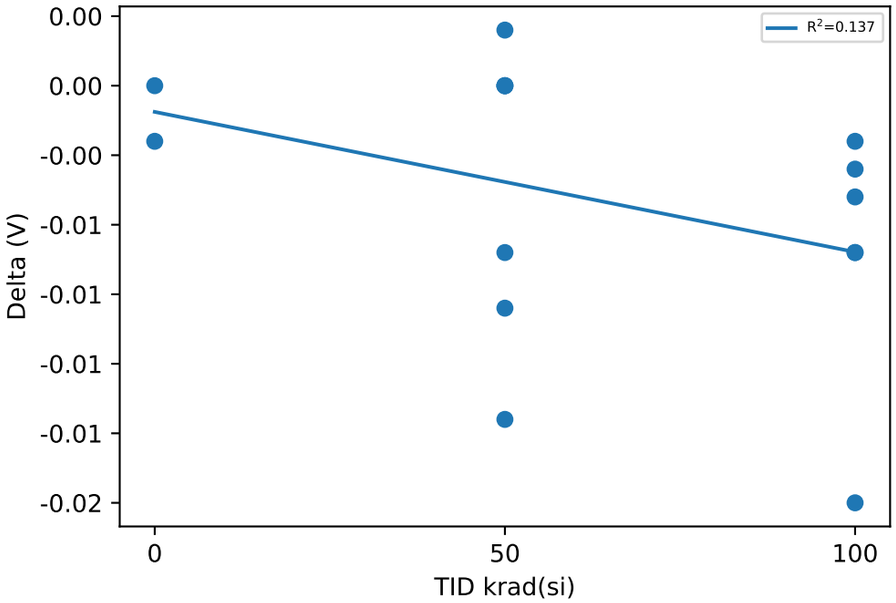
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.103	2.108	2.113	0.0070711	2.097	2.1005	2.104	0.0049497	-0.009	-0.0075	-0.006	0.0021213
50	2.12	2.1323	2.151	0.012566	1.924	2.0001	2.099	0.079976	-0.198	-0.13214	-0.046	0.07844
100	2.113	2.135	2.158	0.016625	1.853	1.9665	2.065	0.10548	-0.264	-0.1685	-0.071	0.10032

Device Test: 6.137 UVLO_RISE(IN_UVLO_RISE/IN///0/0/0/@UVLO_RISE)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



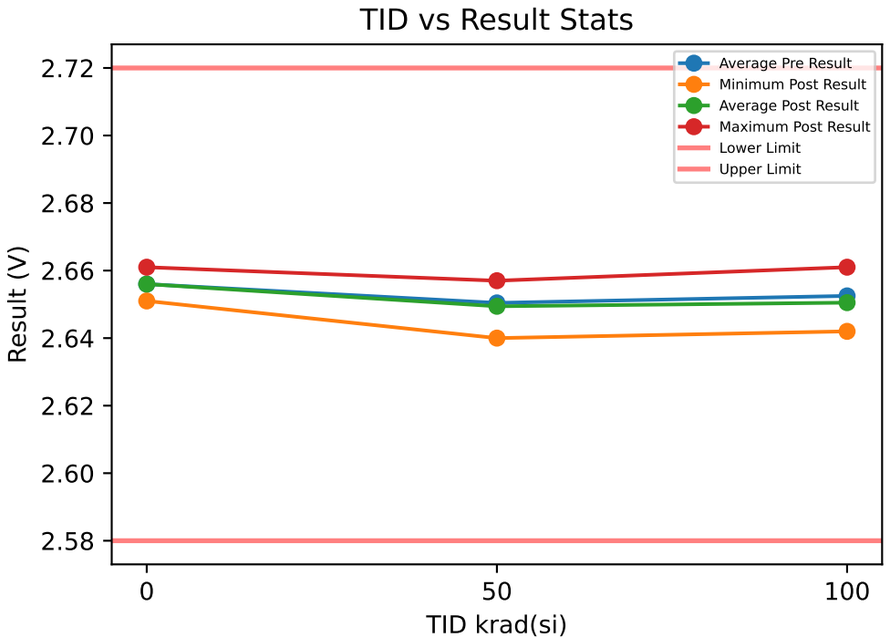
Test Results (Lower Limit = 2.73, Upper Limit = 2.88 (V))

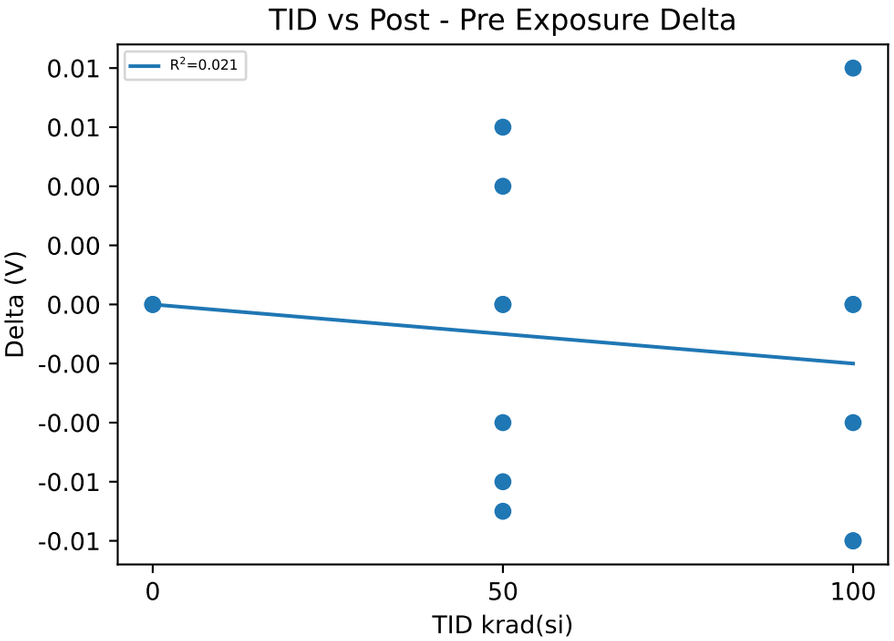
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.807	2.809	0.002
89	50	Biased	2.807	2.795	-0.012
90	50	Biased	2.803	2.803	0
92	50	Biased	2.803	2.795	-0.008
93	50	Unbiased	2.803	2.797	-0.006
94	50	Unbiased	2.795	2.795	0
95	50	Unbiased	2.814	2.814	0
96	100	Biased	2.814	2.799	-0.015
97	100	Biased	2.803	2.799	-0.004
98	100	Biased	2.807	2.801	-0.006
99	100	Unbiased	2.811	2.805	-0.006
100	100	Unbiased	2.793	2.791	-0.002
101	100	Unbiased	2.814	2.811	-0.003
102	0	Correlation	2.811	2.811	0
103	0	Correlation	2.803	2.801	-0.002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.803	2.807	2.811	0.0056569	2.801	2.806	2.811	0.0070711	-0.002	-0.001	0	0.0014142
50	2.795	2.8046	2.814	0.0057694	2.795	2.8011	2.814	0.0077552	-0.012	-0.0034286	0.002	0.0052554
100	2.793	2.807	2.814	0.0080747	2.791	2.801	2.811	0.0066933	-0.015	-0.006	-0.002	0.0046904

Device Test: 6.138 UVLO_FALL(IN_UVLO_FALL/IN///0/0/0/@UVLO_FALL)





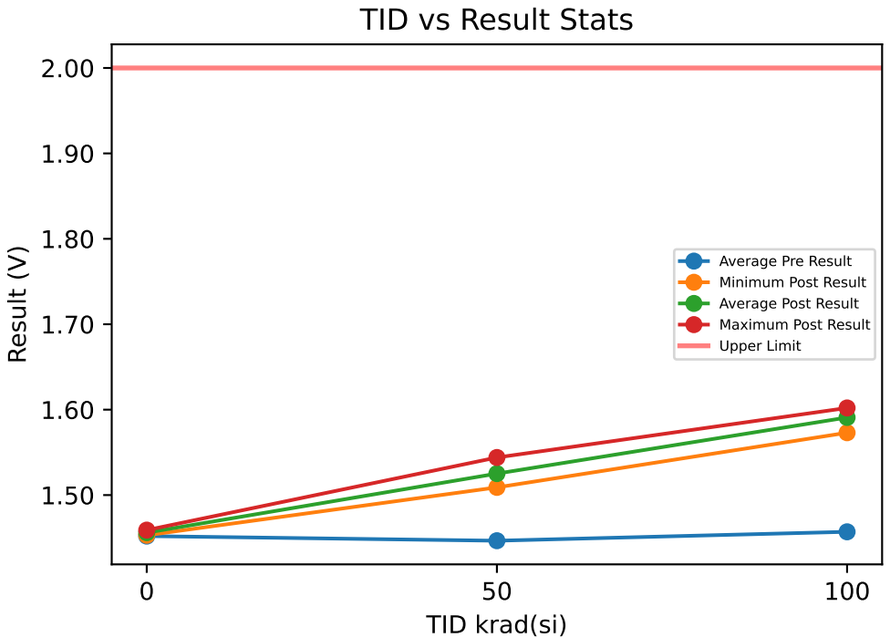
Test Results (Lower Limit = 2.58, Upper Limit = 2.72 (V))

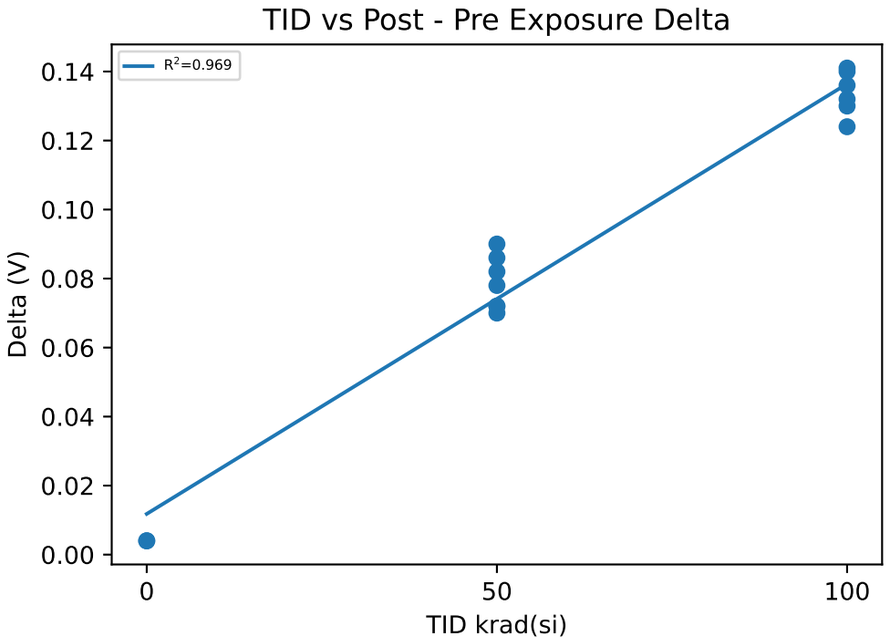
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.653	2.657	0.004
89	50	Biased	2.651	2.647	-0.004
90	50	Biased	2.655	2.649	-0.006
92	50	Biased	2.647	2.64	-0.007
93	50	Unbiased	2.645	2.645	0
94	50	Unbiased	2.645	2.651	0.006
95	50	Unbiased	2.657	2.657	0
96	100	Biased	2.659	2.651	-0.008
97	100	Biased	2.647	2.647	0
98	100	Biased	2.653	2.649	-0.004
99	100	Unbiased	2.653	2.661	0.008
100	100	Unbiased	2.642	2.642	0
101	100	Unbiased	2.661	2.653	-0.008
102	0	Correlation	2.661	2.661	0
103	0	Correlation	2.651	2.651	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.651	2.656	2.661	0.0070711	2.651	2.656	2.661	0.0070711	0	0	0	0
50	2.645	2.6504	2.657	0.0048599	2.64	2.6494	2.657	0.0062144	-0.007	-0.001	0.006	0.0049329
100	2.642	2.6525	2.661	0.0071484	2.642	2.6505	2.661	0.0063797	-0.008	-0.002	0.008	0.0060663

Device Test: 6.139 VIN_VALID(IN_VPOR_RISE_RESETB1/RESETB1/1.6//0/0/0/@VIN_VALID)





Test Results (Upper Limit = 2.0 (V))

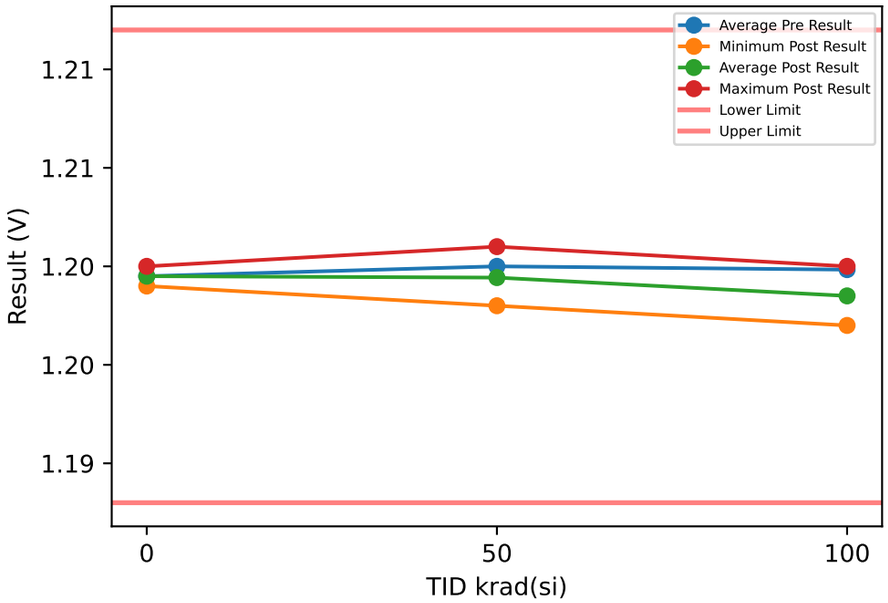
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.441	1.519	0.078
89	50	Biased	1.437	1.509	0.072
90	50	Biased	1.453	1.525	0.072
92	50	Biased	1.474	1.544	0.07
93	50	Unbiased	1.433	1.523	0.09
94	50	Unbiased	1.447	1.529	0.082
95	50	Unbiased	1.441	1.527	0.086
96	100	Biased	1.441	1.573	0.132
97	100	Biased	1.472	1.602	0.13
98	100	Biased	1.449	1.573	0.124
99	100	Unbiased	1.453	1.593	0.14
100	100	Unbiased	1.466	1.602	0.136
101	100	Unbiased	1.461	1.602	0.141
102	0	Correlation	1.449	1.453	0.004
103	0	Correlation	1.455	1.459	0.004

Test Statistics (V)

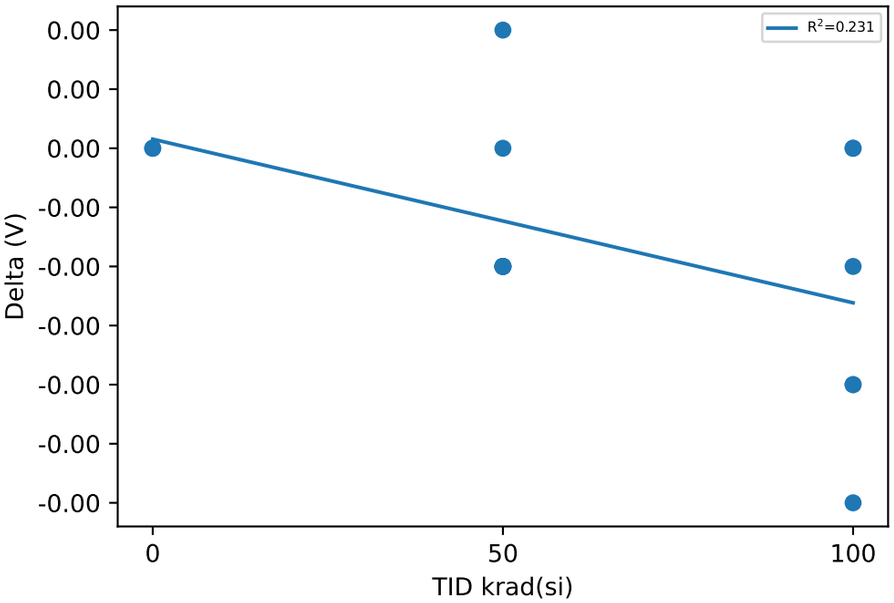
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.449	1.452	1.455	0.0042426	1.453	1.456	1.459	0.0042426	0.004	0.004	0.004	0
50	1.433	1.4466	1.474	0.013734	1.509	1.5251	1.544	0.010621	0.07	0.078571	0.09	0.0077213
100	1.441	1.457	1.472	0.011472	1.573	1.5908	1.602	0.014247	0.124	0.13383	0.141	0.0064627

Device Test: 6.14 REFCAP(REFCAP/REFCAP//14/0/0/0/@REFCAP)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



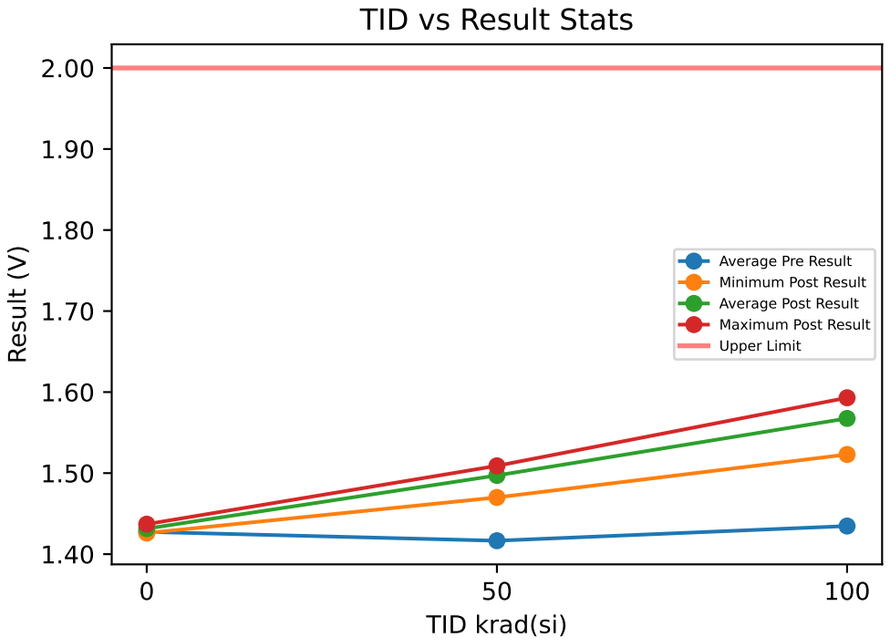
Test Results (Lower Limit = 1.188, Upper Limit = 1.212 (V))

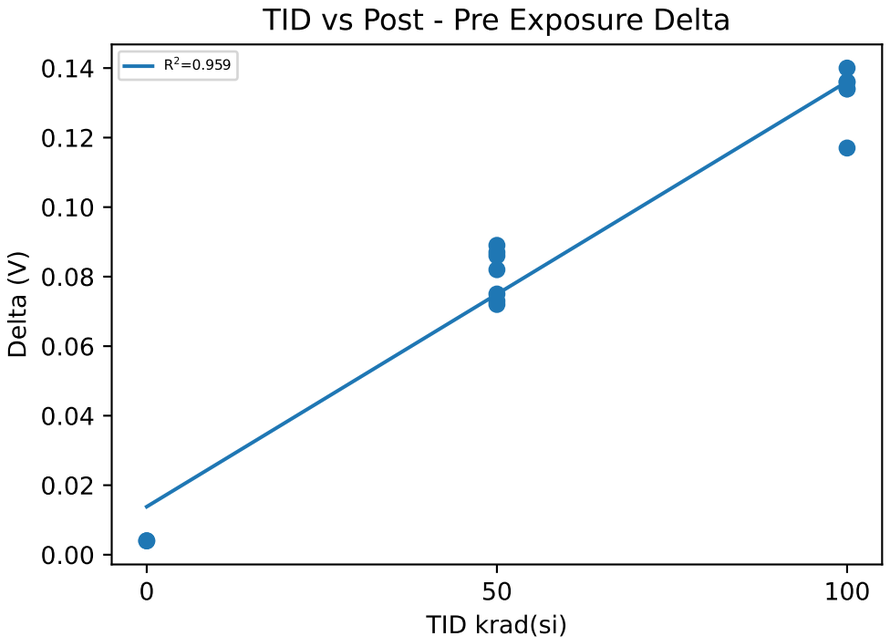
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.199	1.2	0.001
89	50	Biased	1.201	1.2	-0.001
90	50	Biased	1.201	1.201	0
92	50	Biased	1.2	1.199	-0.001
93	50	Unbiased	1.199	1.198	-0.001
94	50	Unbiased	1.201	1.2	-0.001
95	50	Unbiased	1.199	1.198	-0.001
96	100	Biased	1.201	1.198	-0.003
97	100	Biased	1.199	1.197	-0.002
98	100	Biased	1.201	1.2	-0.001
99	100	Unbiased	1.199	1.199	0
100	100	Unbiased	1.199	1.199	0
101	100	Unbiased	1.2	1.198	-0.002
102	0	Correlation	1.199	1.199	0
103	0	Correlation	1.2	1.2	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.199	1.1995	1.2	0.00070711	1.199	1.1995	1.2	0.00070711	0	0	0	0
50	1.199	1.2	1.201	0.001	1.198	1.1994	1.201	0.0011339	-0.001	-0.00057143	0.001	0.0007868
100	1.199	1.1998	1.201	0.00098319	1.197	1.1985	1.2	0.0010488	-0.003	-0.0013333	0	0.0012111

Device Test: 6.140 VIN_VALID(IN_VPOR_RISE_RESETB2/RESETB2/1.6//0/0/0/@VIN_VALID)





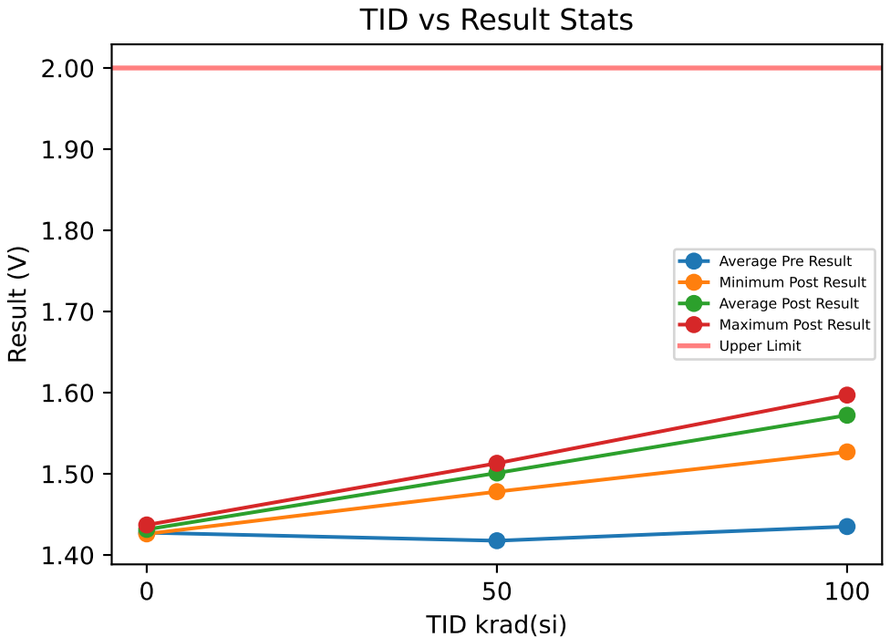
Test Results (Upper Limit = 2.0 (V))

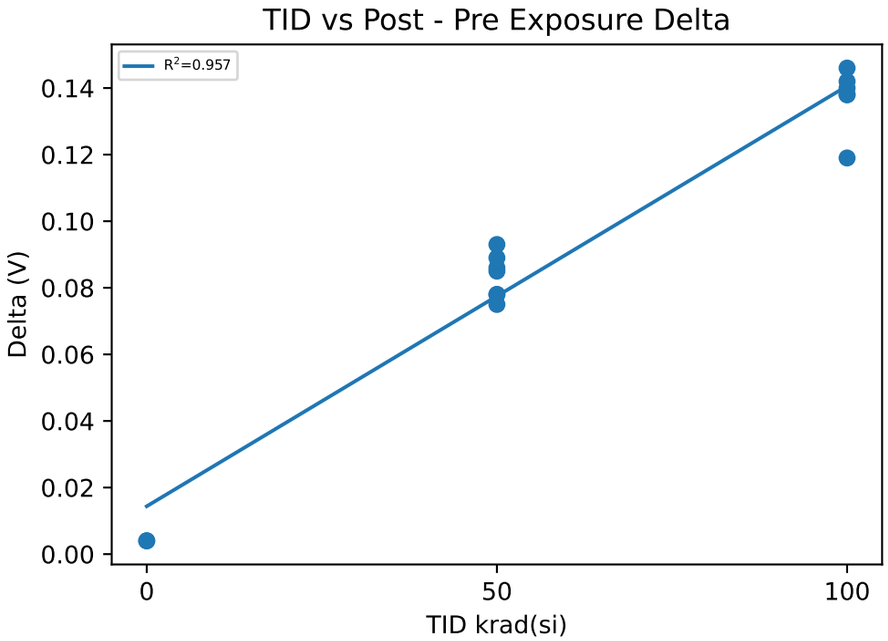
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.414	1.496	0.082
89	50	Biased	1.398	1.47	0.072
90	50	Biased	1.428	1.503	0.075
92	50	Biased	1.426	1.499	0.073
93	50	Unbiased	1.416	1.505	0.089
94	50	Unbiased	1.412	1.498	0.086
95	50	Unbiased	1.422	1.509	0.087
96	100	Biased	1.42	1.554	0.134
97	100	Biased	1.457	1.593	0.136
98	100	Biased	1.406	1.523	0.117
99	100	Unbiased	1.437	1.573	0.136
100	100	Unbiased	1.445	1.579	0.134
101	100	Unbiased	1.443	1.583	0.14
102	0	Correlation	1.433	1.437	0.004
103	0	Correlation	1.422	1.426	0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.422	1.4275	1.433	0.0077782	1.426	1.4315	1.437	0.0077782	0.004	0.004	0.004	0
50	1.398	1.4166	1.428	0.010179	1.47	1.4971	1.509	0.012773	0.072	0.080571	0.089	0.0071381
100	1.406	1.4347	1.457	0.018533	1.523	1.5675	1.593	0.025359	0.117	0.13283	0.14	0.0080602

Device Test: 6.141 VIN_VALID(IN_VPOR_RISE_RESETB3/RESETB3/1.6//0/0/0/@VIN_VALID)





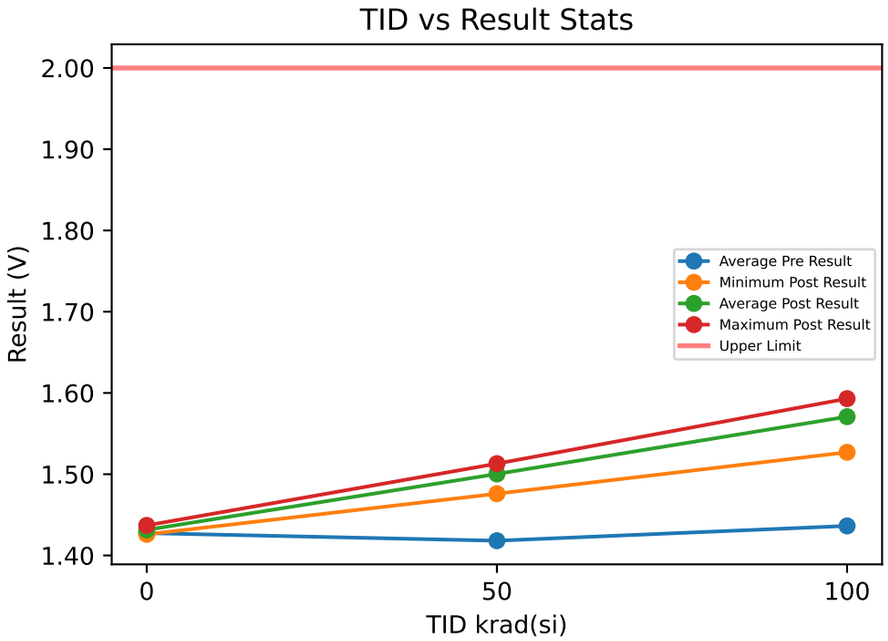
Test Results (Upper Limit = 2.0 (V))

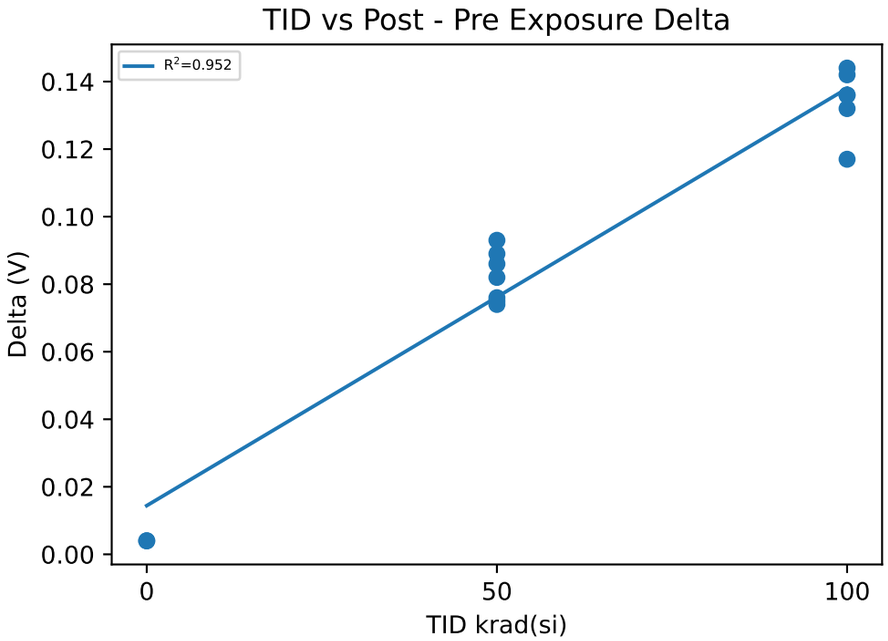
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.416	1.501	0.085
89	50	Biased	1.4	1.478	0.078
90	50	Biased	1.431	1.509	0.078
92	50	Biased	1.428	1.503	0.075
93	50	Unbiased	1.414	1.507	0.093
94	50	Unbiased	1.41	1.496	0.086
95	50	Unbiased	1.424	1.513	0.089
96	100	Biased	1.42	1.558	0.138
97	100	Biased	1.457	1.597	0.14
98	100	Biased	1.408	1.527	0.119
99	100	Unbiased	1.437	1.579	0.142
100	100	Unbiased	1.445	1.583	0.138
101	100	Unbiased	1.443	1.589	0.146
102	0	Correlation	1.433	1.437	0.004
103	0	Correlation	1.422	1.426	0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.422	1.4275	1.433	0.0077782	1.426	1.4315	1.437	0.0077782	0.004	0.004	0.004	0
50	1.4	1.4176	1.431	0.010891	1.478	1.501	1.513	0.011561	0.075	0.083429	0.093	0.0066045
100	1.408	1.435	1.457	0.017922	1.527	1.5722	1.597	0.025709	0.119	0.13717	0.146	0.0093897

Device Test: 6.142 VIN_VALID(IN_VPOR_RISE_RESETB4/RESETB4/1.6//0/0/0/@VIN_VALID)





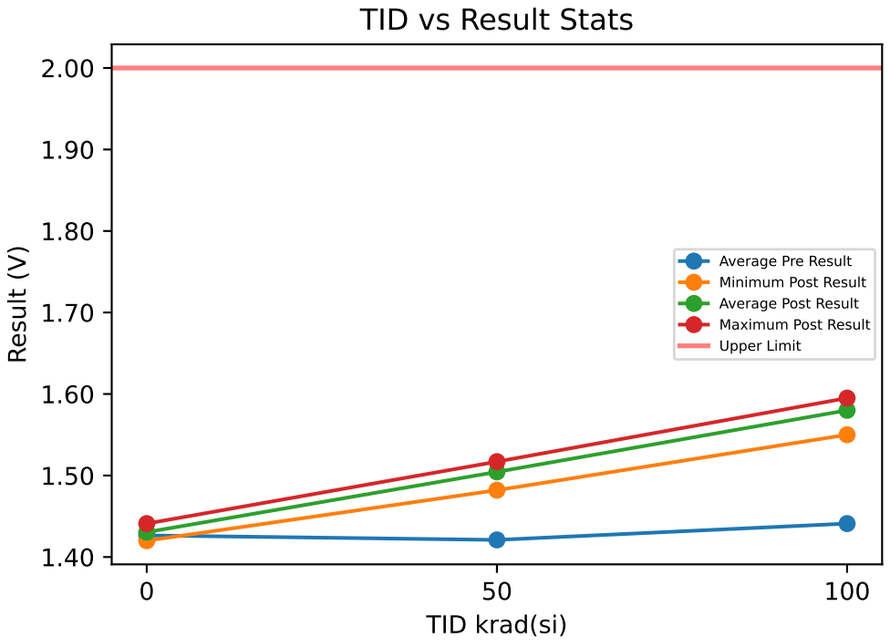
Test Results (Upper Limit = 2.0 (V))

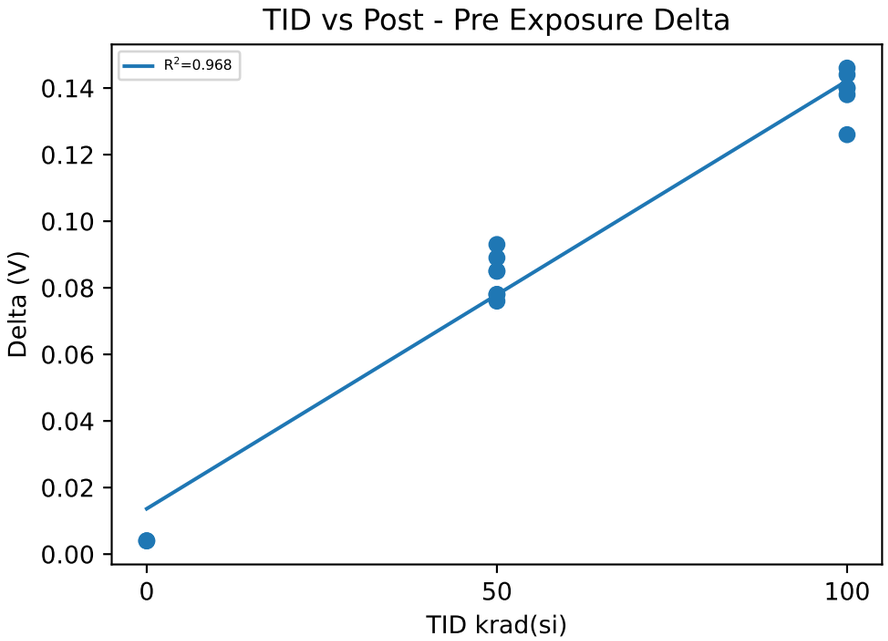
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.416	1.498	0.082
89	50	Biased	1.402	1.476	0.074
90	50	Biased	1.431	1.507	0.076
92	50	Biased	1.43	1.505	0.075
93	50	Unbiased	1.416	1.509	0.093
94	50	Unbiased	1.408	1.494	0.086
95	50	Unbiased	1.424	1.513	0.089
96	100	Biased	1.422	1.554	0.132
97	100	Biased	1.457	1.593	0.136
98	100	Biased	1.41	1.527	0.117
99	100	Unbiased	1.439	1.581	0.142
100	100	Unbiased	1.445	1.581	0.136
101	100	Unbiased	1.445	1.589	0.144
102	0	Correlation	1.433	1.437	0.004
103	0	Correlation	1.422	1.426	0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.422	1.4275	1.433	0.0077782	1.426	1.4315	1.437	0.0077782	0.004	0.004	0.004	0
50	1.402	1.4181	1.431	0.0109	1.476	1.5003	1.513	0.012513	0.074	0.082143	0.093	0.0074706
100	1.41	1.4363	1.457	0.017224	1.527	1.5708	1.593	0.025428	0.117	0.1345	0.144	0.0096281

Device Test: 6.143 VIN_VALID(IN_VPOR_RISE_PWRGD/PWRGD/1.6//0/0/0/@VIN_VALID)





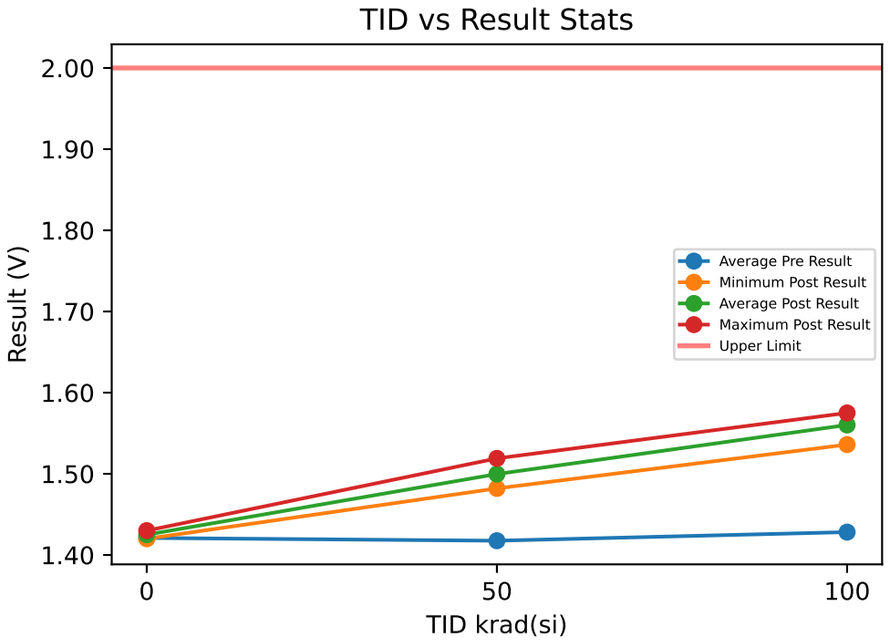
Test Results (Upper Limit = 2.0 (V))

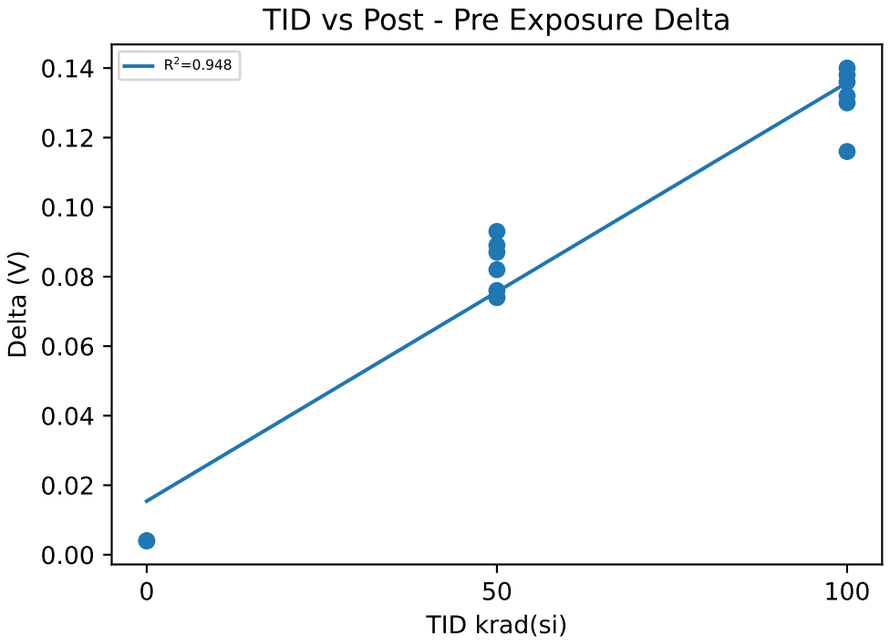
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.422	1.507	0.085
89	50	Biased	1.412	1.488	0.076
90	50	Biased	1.439	1.517	0.078
92	50	Biased	1.435	1.513	0.078
93	50	Unbiased	1.414	1.507	0.093
94	50	Unbiased	1.397	1.482	0.085
95	50	Unbiased	1.428	1.517	0.089
96	100	Biased	1.424	1.564	0.14
97	100	Biased	1.455	1.595	0.14
98	100	Biased	1.424	1.55	0.126
99	100	Unbiased	1.443	1.587	0.144
100	100	Unbiased	1.451	1.589	0.138
101	100	Unbiased	1.449	1.595	0.146
102	0	Correlation	1.437	1.441	0.004
103	0	Correlation	1.416	1.42	0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.416	1.4265	1.437	0.014849	1.42	1.4305	1.441	0.014849	0.004	0.004	0.004	0
50	1.397	1.421	1.439	0.014583	1.482	1.5044	1.517	0.013998	0.076	0.083429	0.093	0.0063471
100	1.424	1.441	1.455	0.013726	1.55	1.58	1.595	0.018633	0.126	0.139	0.146	0.0070143

Device Test: 6.144 VIN_VALID(IN_VPOR_RISE_RESETB1/RESETB1/7//0/0/0/@VIN_VALID)





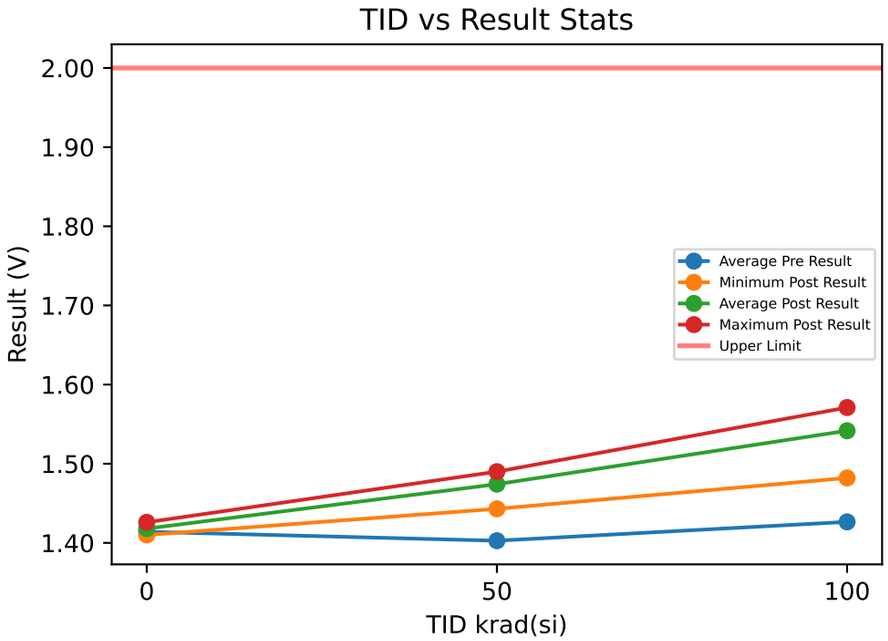
Test Results (Upper Limit = 2.0 (V))

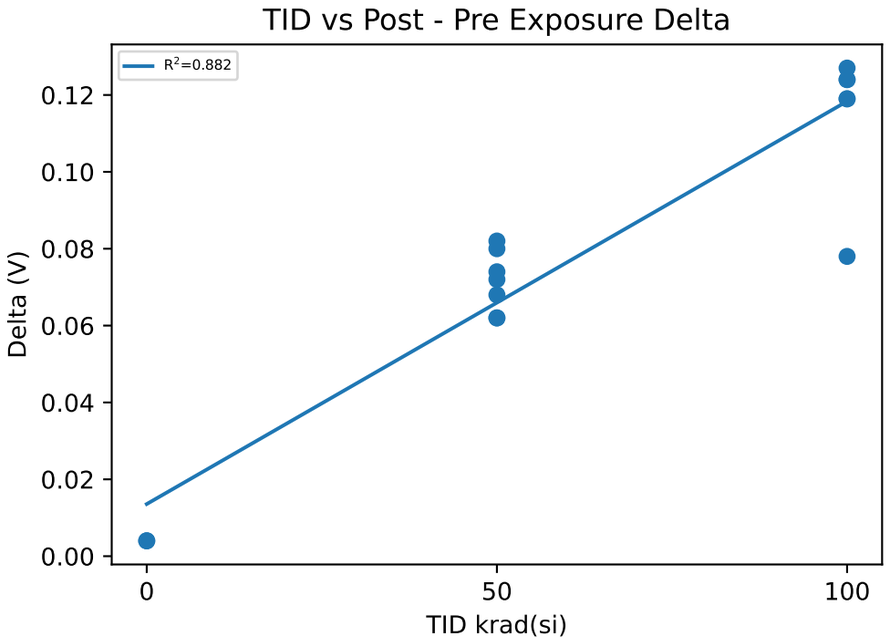
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.412	1.494	0.082
89	50	Biased	1.408	1.482	0.074
90	50	Biased	1.422	1.498	0.076
92	50	Biased	1.445	1.519	0.074
93	50	Unbiased	1.406	1.499	0.093
94	50	Unbiased	1.418	1.505	0.087
95	50	Unbiased	1.412	1.501	0.089
96	100	Biased	1.412	1.542	0.13
97	100	Biased	1.443	1.575	0.132
98	100	Biased	1.42	1.536	0.116
99	100	Unbiased	1.424	1.562	0.138
100	100	Unbiased	1.437	1.573	0.136
101	100	Unbiased	1.433	1.573	0.14
102	0	Correlation	1.416	1.42	0.004
103	0	Correlation	1.426	1.43	0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.416	1.421	1.426	0.0070711	1.42	1.425	1.43	0.0070711	0.004	0.004	0.004	0
50	1.406	1.4176	1.445	0.01329	1.482	1.4997	1.519	0.011191	0.074	0.082143	0.093	0.0077337
100	1.412	1.4282	1.443	0.011548	1.536	1.5602	1.575	0.017128	0.116	0.132	0.14	0.0086718

Device Test: 6.145 VIN_VALID(IN_VPOR_RISE_RESETB2/RESETB2/7//0/0/0/@VIN_VALID)





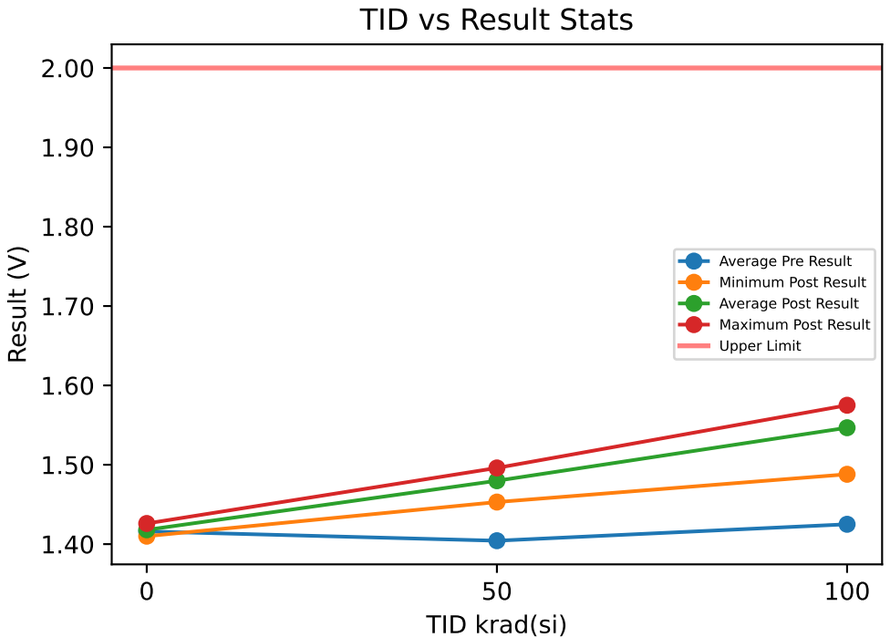
Test Results (Upper Limit = 2.0 (V))

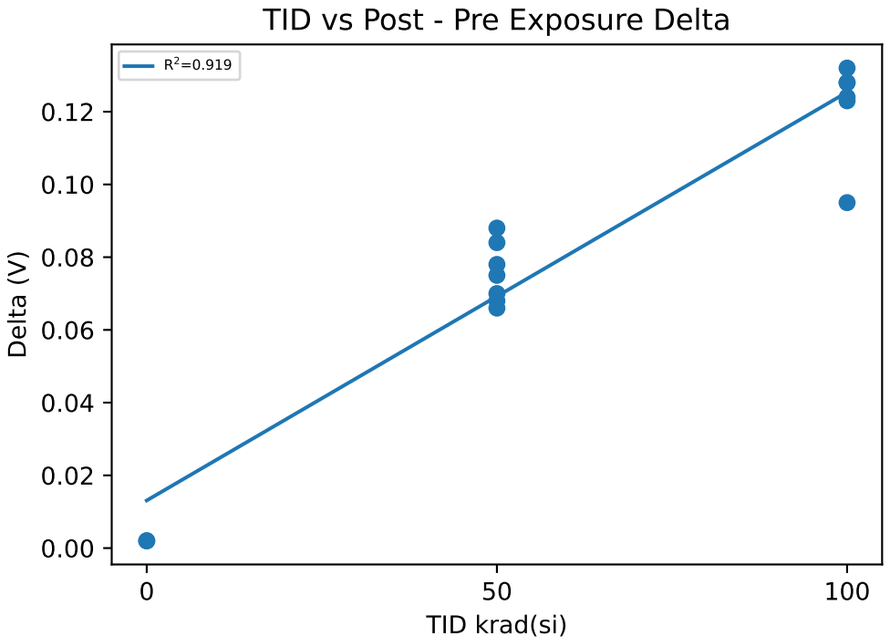
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.402	1.474	0.072
89	50	Biased	1.381	1.443	0.062
90	50	Biased	1.416	1.484	0.068
92	50	Biased	1.406	1.468	0.062
93	50	Unbiased	1.406	1.488	0.082
94	50	Unbiased	1.398	1.472	0.074
95	50	Unbiased	1.41	1.49	0.08
96	100	Biased	1.412	1.531	0.119
97	100	Biased	1.447	1.571	0.124
98	100	Biased	1.404	1.482	0.078
99	100	Unbiased	1.43	1.554	0.124
100	100	Unbiased	1.431	1.55	0.119
101	100	Unbiased	1.435	1.562	0.127
102	0	Correlation	1.422	1.426	0.004
103	0	Correlation	1.406	1.41	0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.406	1.414	1.422	0.011314	1.41	1.418	1.426	0.011314	0.004	0.004	0.004	0
50	1.381	1.4027	1.416	0.011146	1.443	1.4741	1.49	0.016088	0.062	0.071429	0.082	0.0079762
100	1.404	1.4265	1.447	0.015758	1.482	1.5417	1.571	0.032154	0.078	0.11517	0.127	0.018476

Device Test: 6.146 VIN_VALID(IN_VPOR_RISE_RESETB3/RESETB3/7//0/0/0/@VIN_VALID)





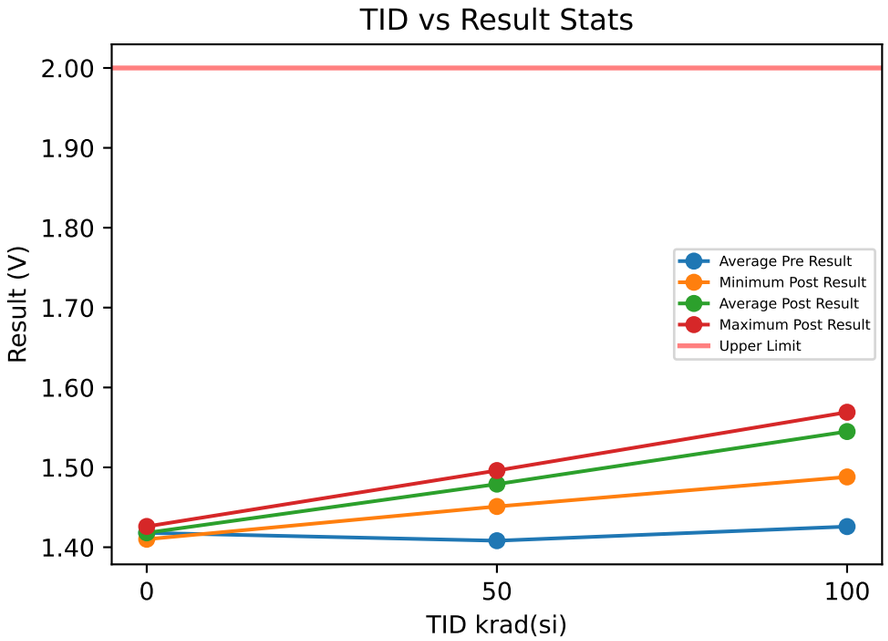
Test Results (Upper Limit = 2.0 (V))

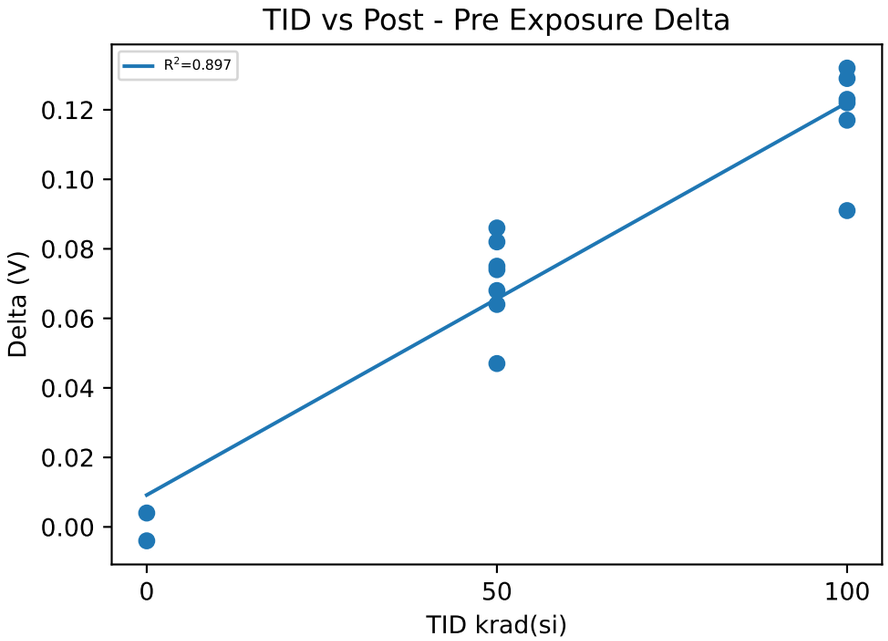
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.404	1.482	0.078
89	50	Biased	1.385	1.453	0.068
90	50	Biased	1.42	1.49	0.07
92	50	Biased	1.41	1.476	0.066
93	50	Unbiased	1.404	1.492	0.088
94	50	Unbiased	1.395	1.47	0.075
95	50	Unbiased	1.412	1.496	0.084
96	100	Biased	1.412	1.536	0.124
97	100	Biased	1.447	1.575	0.128
98	100	Biased	1.393	1.488	0.095
99	100	Unbiased	1.43	1.558	0.128
100	100	Unbiased	1.433	1.556	0.123
101	100	Unbiased	1.435	1.567	0.132
102	0	Correlation	1.424	1.426	0.002
103	0	Correlation	1.408	1.41	0.002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.408	1.416	1.424	0.011314	1.41	1.418	1.426	0.011314	0.002	0.002	0.002	0
50	1.385	1.4043	1.42	0.011528	1.453	1.4799	1.496	0.014994	0.066	0.075571	0.088	0.0082837
100	1.393	1.425	1.447	0.019318	1.488	1.5467	1.575	0.031583	0.095	0.12167	0.132	0.013456

Device Test: 6.147 VIN_VALID(IN_VPOR_RISE_RESETB4/RESETB4/7//0/0/0/@VIN_VALID)





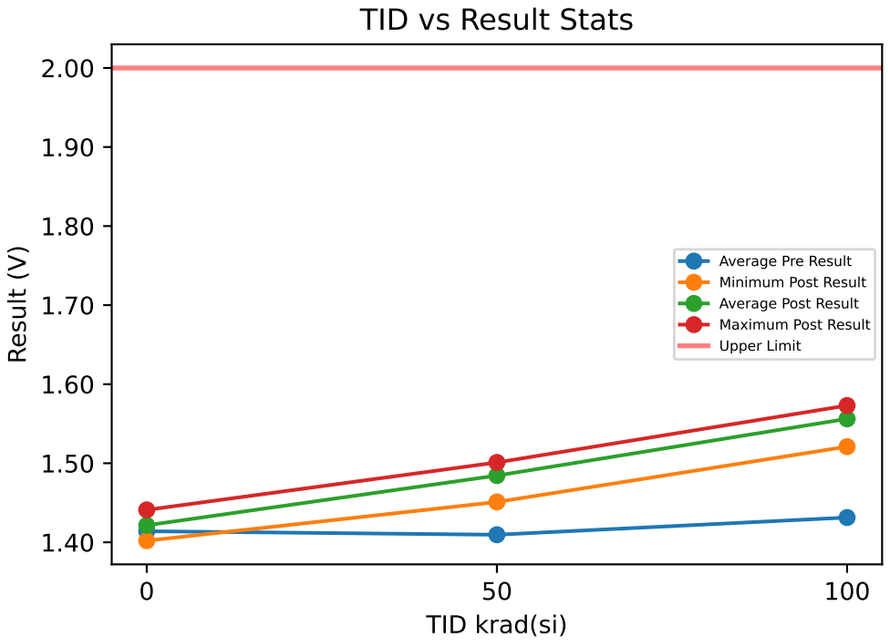
Test Results (Upper Limit = 2.0 (V))

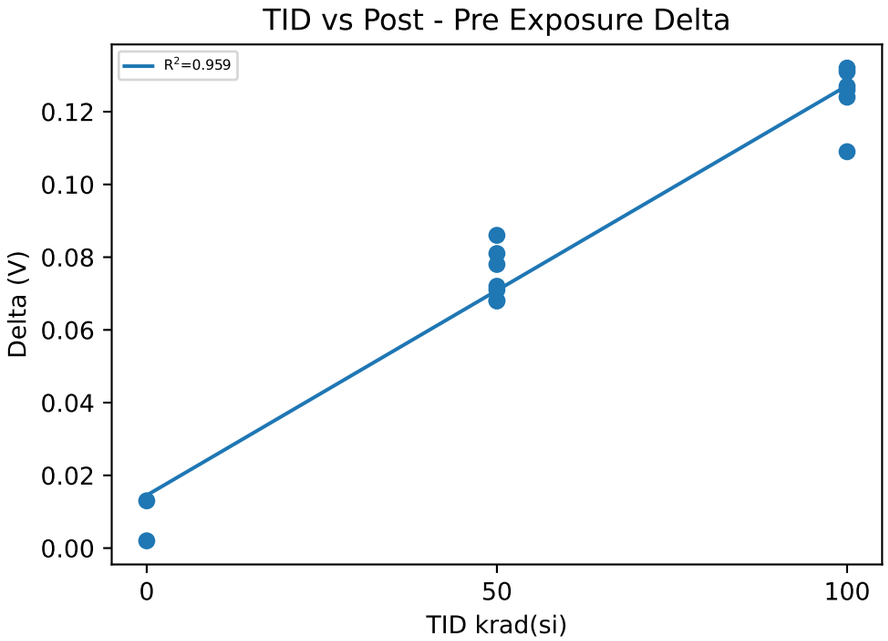
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.404	1.478	0.074
89	50	Biased	1.387	1.451	0.064
90	50	Biased	1.422	1.49	0.068
92	50	Biased	1.431	1.478	0.047
93	50	Unbiased	1.406	1.492	0.086
94	50	Unbiased	1.393	1.468	0.075
95	50	Unbiased	1.414	1.496	0.082
96	100	Biased	1.414	1.531	0.117
97	100	Biased	1.447	1.569	0.122
98	100	Biased	1.397	1.488	0.091
99	100	Unbiased	1.431	1.56	0.129
100	100	Unbiased	1.431	1.554	0.123
101	100	Unbiased	1.435	1.567	0.132
102	0	Correlation	1.43	1.426	-0.004
103	0	Correlation	1.406	1.41	0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.406	1.418	1.43	0.016971	1.41	1.418	1.426	0.011314	-0.004	0	0.004	0.0056569
50	1.387	1.4081	1.431	0.015529	1.451	1.479	1.496	0.015737	0.047	0.070857	0.086	0.012941
100	1.397	1.4258	1.447	0.017646	1.488	1.5448	1.569	0.031019	0.091	0.119	0.132	0.014711

Device Test: 6.148 VIN_VALID(IN_VPOR_RISE_PWRGD/PWRGD/7//0/0/0/@VIN_VALID)





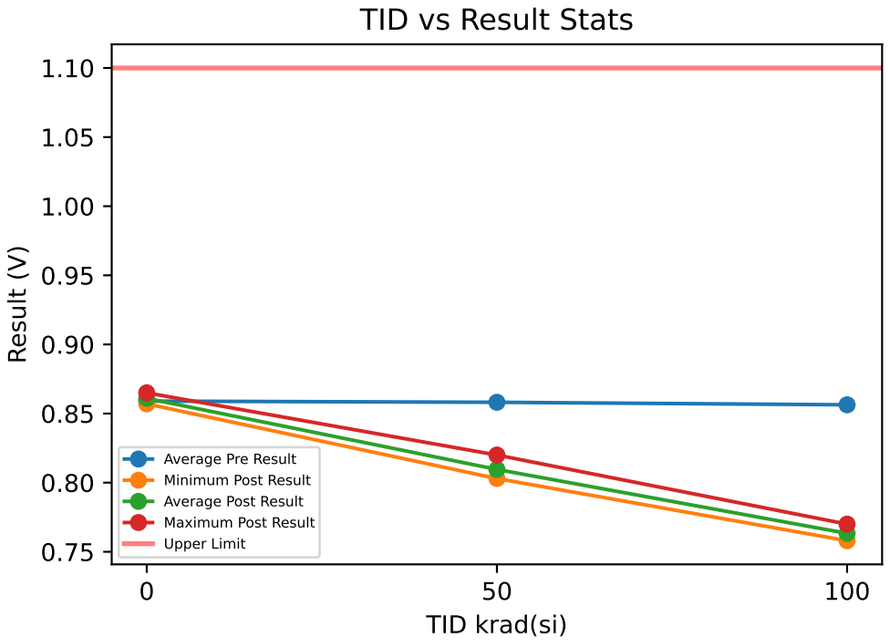
Test Results (Upper Limit = 2.0 (V))

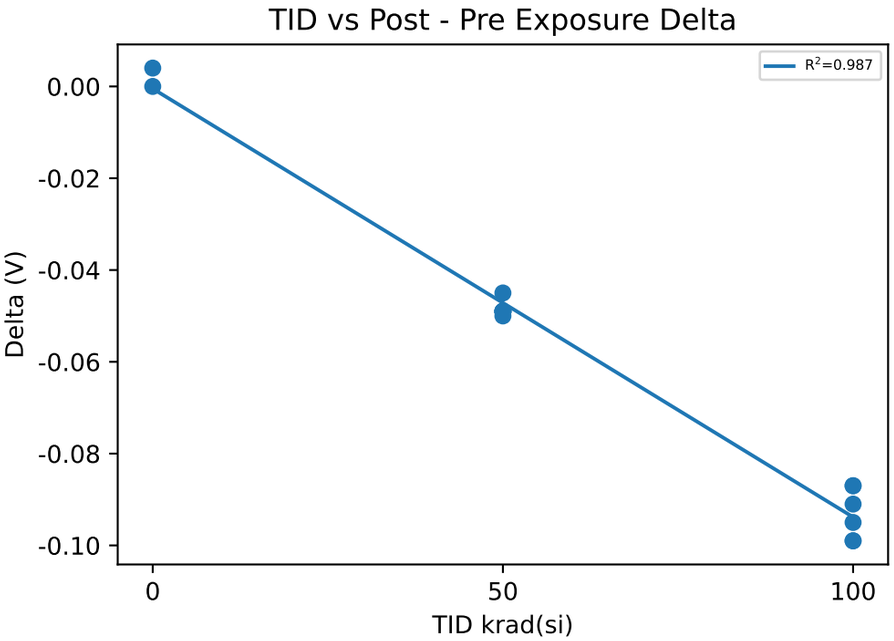
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.412	1.49	0.078
89	50	Biased	1.4	1.468	0.068
90	50	Biased	1.43	1.501	0.071
92	50	Biased	1.422	1.49	0.068
93	50	Unbiased	1.404	1.49	0.086
94	50	Unbiased	1.379	1.451	0.072
95	50	Unbiased	1.42	1.501	0.081
96	100	Biased	1.416	1.542	0.126
97	100	Biased	1.445	1.569	0.124
98	100	Biased	1.412	1.521	0.109
99	100	Unbiased	1.435	1.566	0.131
100	100	Unbiased	1.439	1.566	0.127
101	100	Unbiased	1.441	1.573	0.132
102	0	Correlation	1.428	1.441	0.013
103	0	Correlation	1.4	1.402	0.002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.4	1.414	1.428	0.019799	1.402	1.4215	1.441	0.027577	0.002	0.0075	0.013	0.0077782
50	1.379	1.4096	1.43	0.017048	1.451	1.4844	1.501	0.018393	0.068	0.074857	0.086	0.0069385
100	1.412	1.4313	1.445	0.013866	1.521	1.5562	1.573	0.02039	0.109	0.12483	0.132	0.0083287

Device Test: 6.149 VPULLUP_VALID(PU1_VPOR_RISE_RESETB1/RESETB1//0/0/0/0.1/@VPULLUP_VALID)





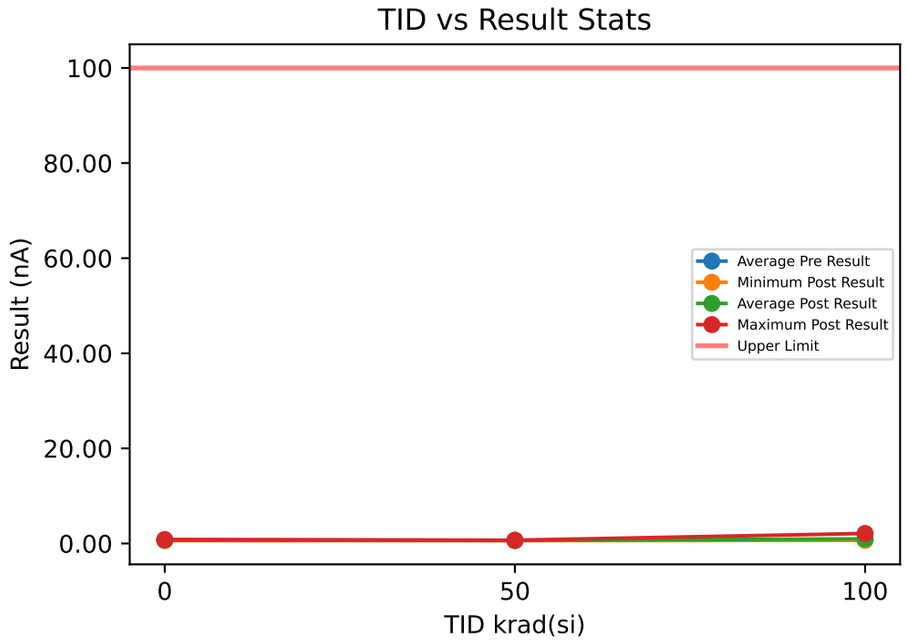
Test Results (Upper Limit = 1.1 (V))

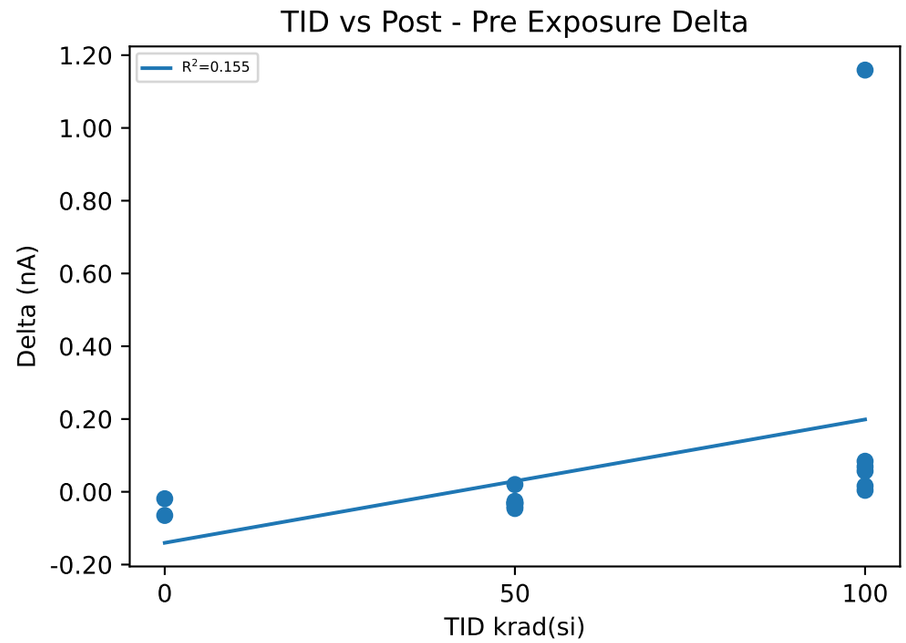
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.853	0.803	-0.05
89	50	Biased	0.857	0.808	-0.049
90	50	Biased	0.857	0.808	-0.049
92	50	Biased	0.861	0.812	-0.049
93	50	Unbiased	0.857	0.808	-0.049
94	50	Unbiased	0.865	0.82	-0.045
95	50	Unbiased	0.857	0.808	-0.049
96	100	Biased	0.857	0.762	-0.095
97	100	Biased	0.857	0.758	-0.099
98	100	Biased	0.857	0.758	-0.099
99	100	Unbiased	0.857	0.766	-0.091
100	100	Unbiased	0.853	0.766	-0.087
101	100	Unbiased	0.857	0.77	-0.087
102	0	Correlation	0.853	0.857	0.004
103	0	Correlation	0.865	0.865	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.853	0.859	0.865	0.0084853	0.857	0.861	0.865	0.0056569	0	0.002	0.004	0.0028284
50	0.853	0.85814	0.865	0.0038048	0.803	0.80957	0.82	0.005287	-0.05	-0.048571	-0.045	0.0016183
100	0.853	0.85633	0.857	0.001633	0.758	0.76333	0.77	0.0048442	-0.099	-0.093	-0.087	0.0055136

Device Test: 6.15 ILKG_SR_UVLO(ILKG_SR_UVLOb/SR_UVLOb//3/0/0/0/@ILKG_SR_UVLO)





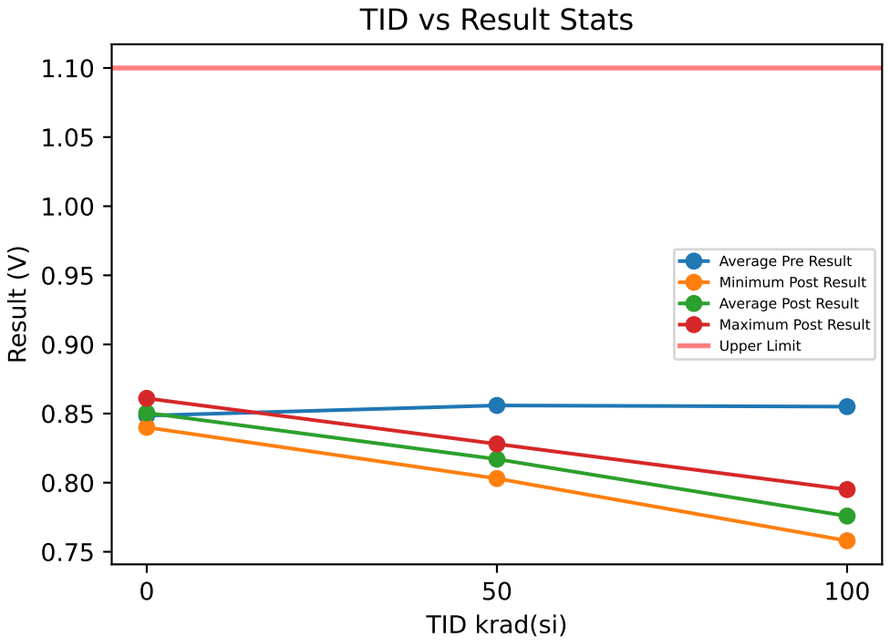
Test Results (Upper Limit = 100.0 (nA))

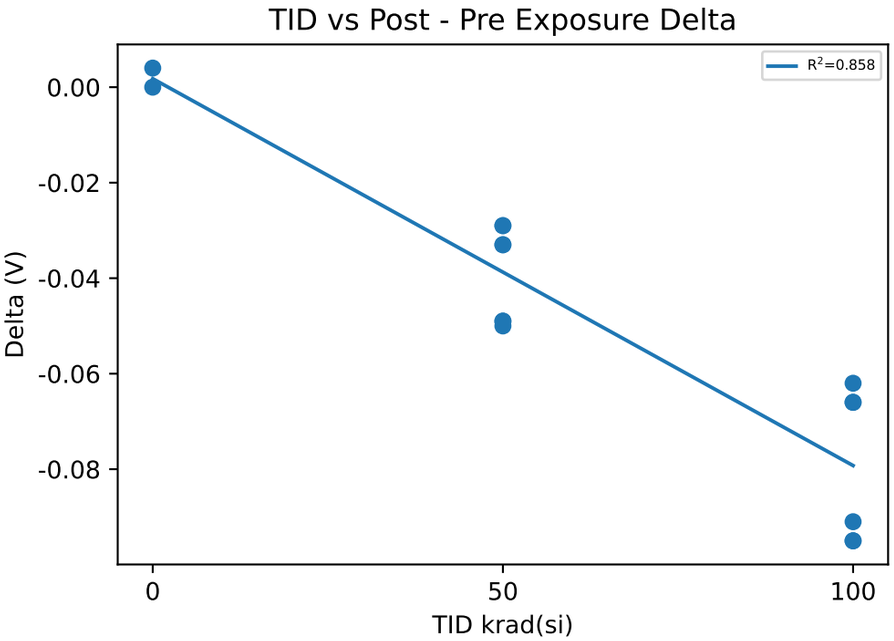
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.681	0.635	-0.046
89	50	Biased	0.64	0.608	-0.032
90	50	Biased	0.667	0.636	-0.031
92	50	Biased	0.633	0.601	-0.032
93	50	Unbiased	0.671	0.63	-0.041
94	50	Unbiased	0.666	0.686	0.02
95	50	Unbiased	0.647	0.621	-0.026
96	100	Biased	0.947	2.106	1.159
97	100	Biased	0.618	0.675	0.057
98	100	Biased	0.608	0.692	0.084
99	100	Unbiased	0.605	0.674	0.069
100	100	Unbiased	0.963	0.967	0.004
101	100	Unbiased	0.66	0.676	0.016
102	0	Correlation	0.89	0.825	-0.065
103	0	Correlation	0.601	0.582	-0.019

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.601	0.7455	0.89	0.20435	0.582	0.7035	0.825	0.17183	-0.065	-0.042	-0.019	0.032527
50	0.633	0.65786	0.681	0.017855	0.601	0.631	0.686	0.027677	-0.046	-0.026857	0.02	0.021729
100	0.605	0.7335	0.963	0.17278	0.674	0.965	2.106	0.57074	0.004	0.2315	1.159	0.45543

Device Test: 6.150 VPULLUP_VALID(PU1_VPOR_RISE_RESETB2/RESETB2//0/0/0/0.1/@VPULLUP_VALID)





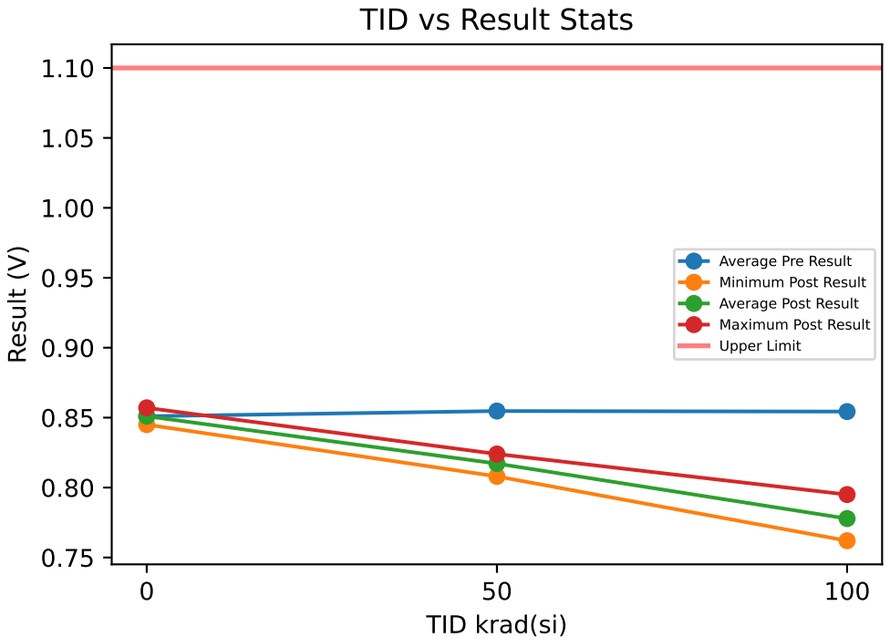
Test Results (Upper Limit = 1.1 (V))

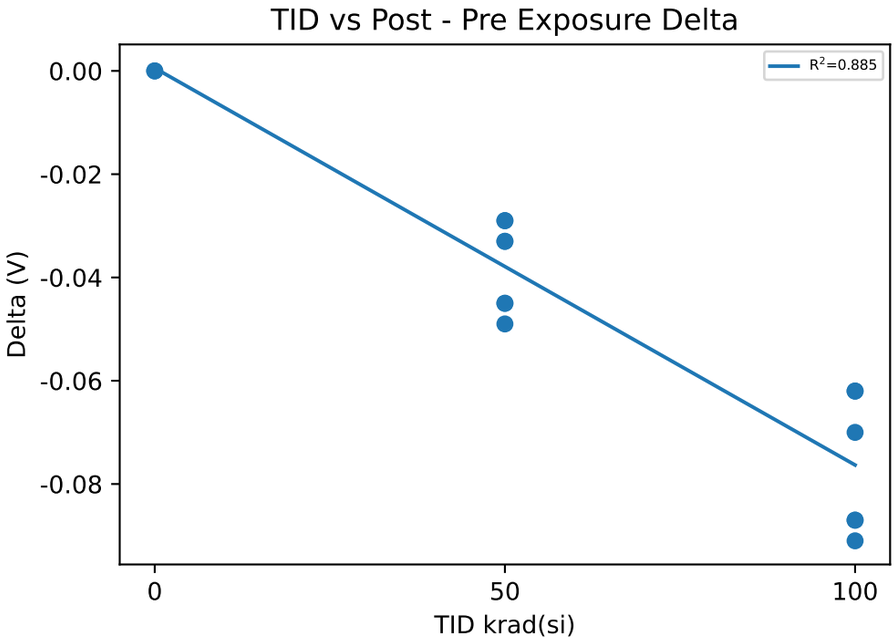
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.853	0.824	-0.029
89	50	Biased	0.853	0.82	-0.033
90	50	Biased	0.853	0.824	-0.029
92	50	Biased	0.861	0.828	-0.033
93	50	Unbiased	0.857	0.808	-0.049
94	50	Unbiased	0.861	0.812	-0.049
95	50	Unbiased	0.853	0.803	-0.05
96	100	Biased	0.857	0.795	-0.062
97	100	Biased	0.857	0.791	-0.066
98	100	Biased	0.853	0.787	-0.066
99	100	Unbiased	0.857	0.762	-0.095
100	100	Unbiased	0.853	0.762	-0.091
101	100	Unbiased	0.853	0.758	-0.095
102	0	Correlation	0.84	0.84	0
103	0	Correlation	0.857	0.861	0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.84	0.8485	0.857	0.012021	0.84	0.8505	0.861	0.014849	0	0.002	0.004	0.0028284
50	0.853	0.85586	0.861	0.0038048	0.803	0.817	0.828	0.0093986	-0.05	-0.038857	-0.029	0.0099403
100	0.853	0.855	0.857	0.0021909	0.758	0.77583	0.795	0.016869	-0.095	-0.079167	-0.062	0.016018

Device Test: 6.151 VPULLUP_VALID(PU1_VPOR_RISE_RESETB3/RESETB3//0/0/0/0.1/@VPULLUP_VALID)





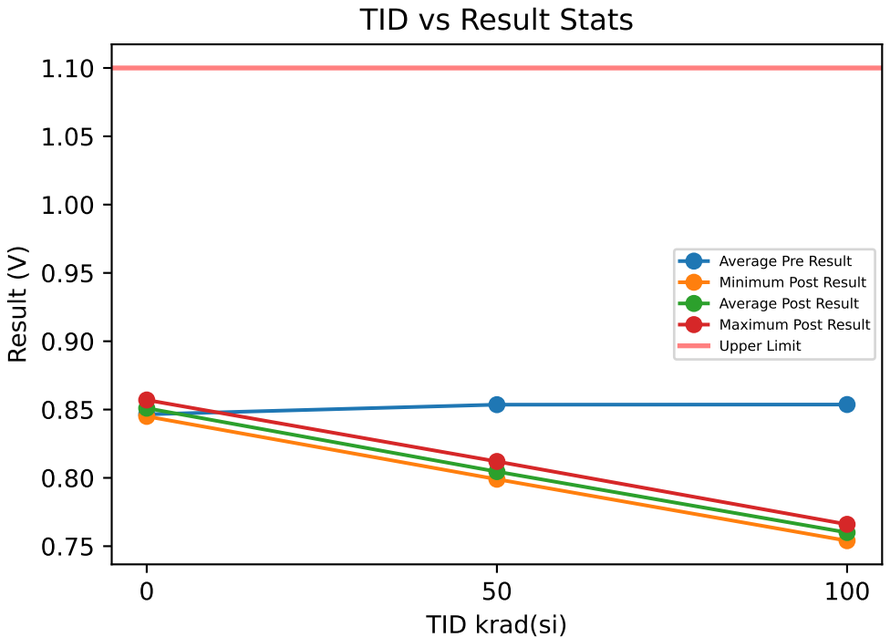
Test Results (Upper Limit = 1.1 (V))

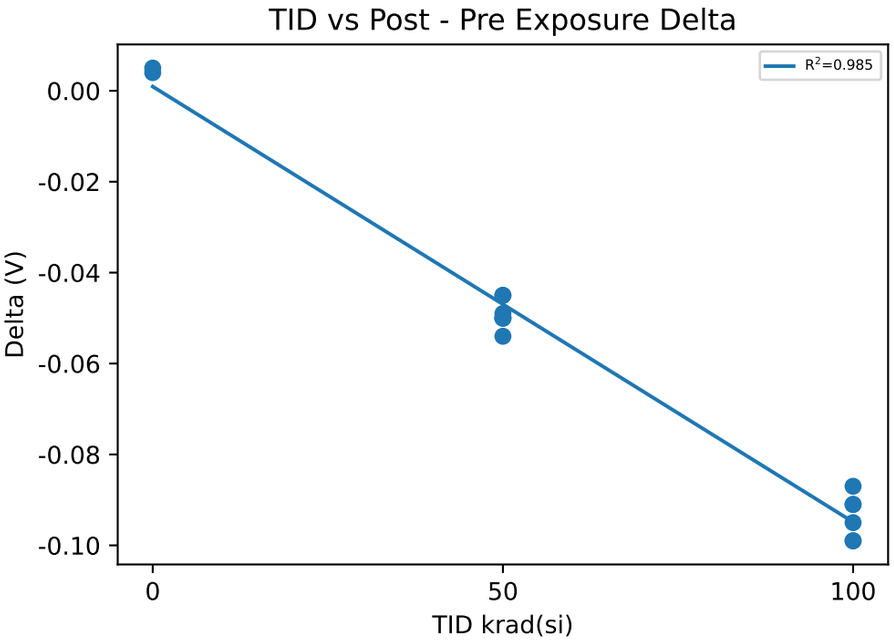
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.849	0.82	-0.029
89	50	Biased	0.857	0.824	-0.033
90	50	Biased	0.853	0.824	-0.029
92	50	Biased	0.857	0.824	-0.033
93	50	Unbiased	0.857	0.808	-0.049
94	50	Unbiased	0.857	0.812	-0.045
95	50	Unbiased	0.853	0.808	-0.045
96	100	Biased	0.857	0.795	-0.062
97	100	Biased	0.857	0.795	-0.062
98	100	Biased	0.853	0.783	-0.07
99	100	Unbiased	0.857	0.77	-0.087
100	100	Unbiased	0.853	0.762	-0.091
101	100	Unbiased	0.849	0.762	-0.087
102	0	Correlation	0.845	0.845	0
103	0	Correlation	0.857	0.857	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.845	0.851	0.857	0.0084853	0.845	0.851	0.857	0.0084853	0	0	0	0
50	0.849	0.85471	0.857	0.0031472	0.808	0.81714	0.824	0.0075593	-0.049	-0.037571	-0.029	0.0084628
100	0.849	0.85433	0.857	0.003266	0.762	0.77783	0.795	0.015355	-0.091	-0.0765	-0.062	0.013368

Device Test: 6.152 VPULLUP_VALID(PU1_VPOR_RISE_RESETB4/RESETB4//0/0/0/0.1/@VPULLUP_VALID)





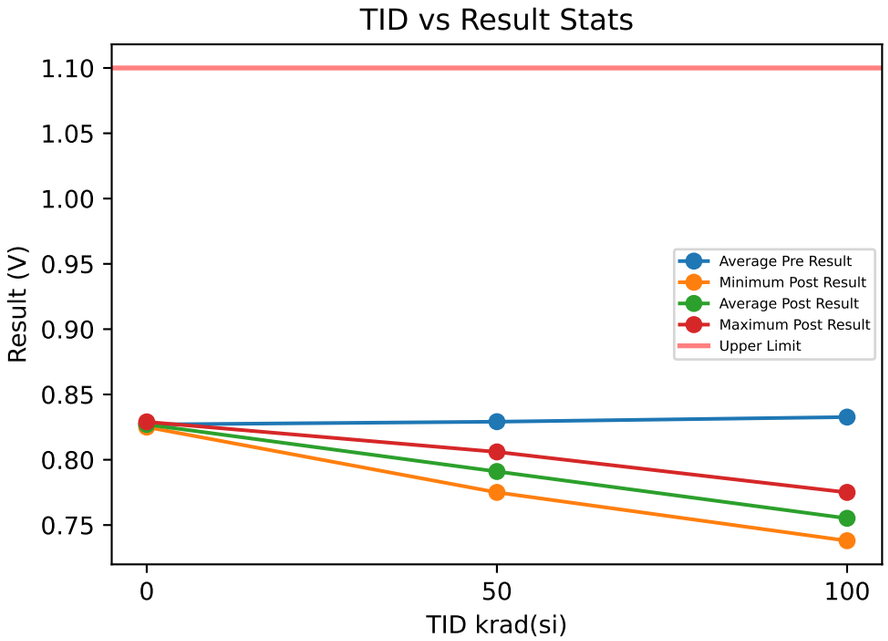
Test Results (Upper Limit = 1.1 (V))

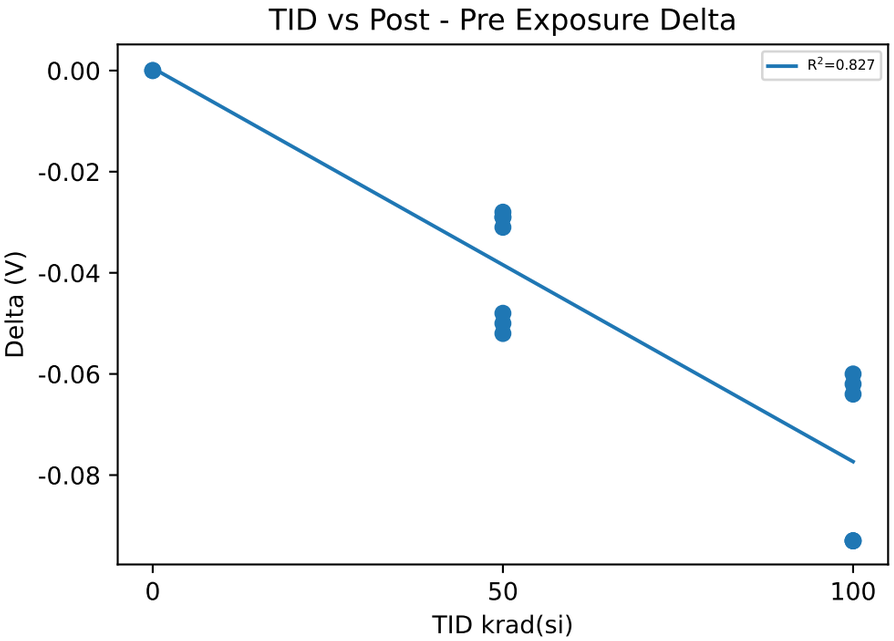
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.849	0.799	-0.05
89	50	Biased	0.849	0.799	-0.05
90	50	Biased	0.853	0.803	-0.05
92	50	Biased	0.857	0.803	-0.054
93	50	Unbiased	0.857	0.808	-0.049
94	50	Unbiased	0.857	0.812	-0.045
95	50	Unbiased	0.853	0.808	-0.045
96	100	Biased	0.853	0.758	-0.095
97	100	Biased	0.853	0.754	-0.099
98	100	Biased	0.853	0.754	-0.099
99	100	Unbiased	0.857	0.766	-0.091
100	100	Unbiased	0.853	0.766	-0.087
101	100	Unbiased	0.853	0.762	-0.091
102	0	Correlation	0.84	0.845	0.005
103	0	Correlation	0.853	0.857	0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.84	0.8465	0.853	0.0091924	0.845	0.851	0.857	0.0084853	0.004	0.0045	0.005	0.00070711
50	0.849	0.85357	0.857	0.0035989	0.799	0.80457	0.812	0.0049281	-0.054	-0.049	-0.045	0.0031623
100	0.853	0.85367	0.857	0.001633	0.754	0.76	0.766	0.0055136	-0.099	-0.093667	-0.087	0.0048442

Device Test: 6.153 VPULLUP_VALID(PU2_VPOR_RISE_PWRGD/PWRGD//0/0/0/0.1/@VPULLUP_VALID)





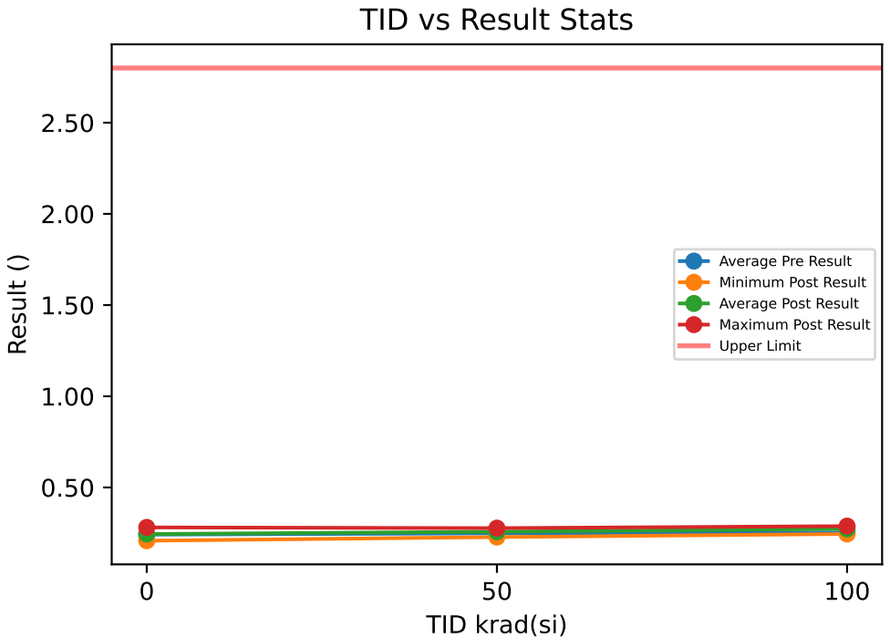
Test Results (Upper Limit = 1.1 (V))

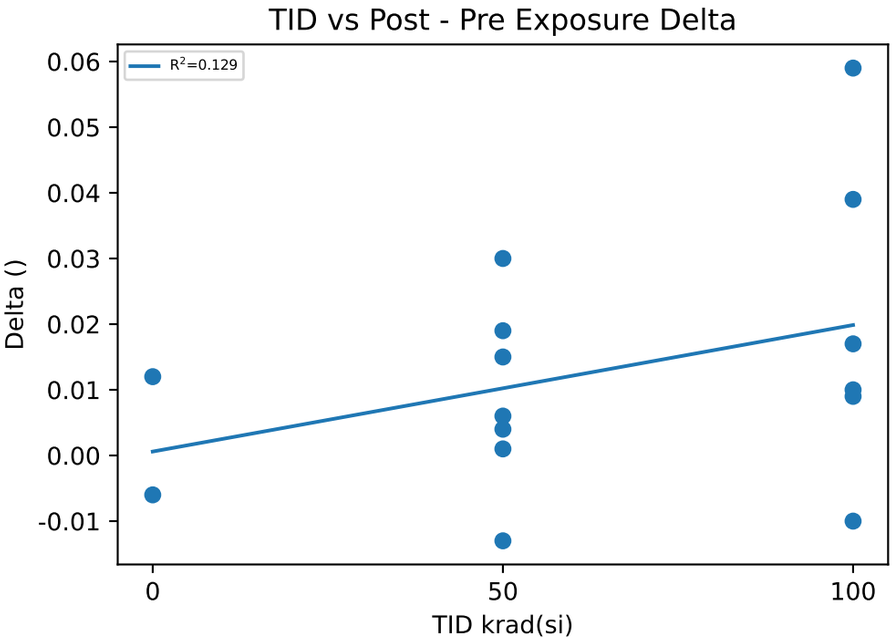
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.822	0.794	-0.028
89	50	Biased	0.825	0.796	-0.029
90	50	Biased	0.827	0.798	-0.029
92	50	Biased	0.837	0.806	-0.031
93	50	Unbiased	0.833	0.783	-0.05
94	50	Unbiased	0.827	0.775	-0.052
95	50	Unbiased	0.833	0.785	-0.048
96	100	Biased	0.831	0.771	-0.06
97	100	Biased	0.837	0.775	-0.062
98	100	Biased	0.827	0.763	-0.064
99	100	Unbiased	0.835	0.742	-0.093
100	100	Unbiased	0.835	0.742	-0.093
101	100	Unbiased	0.831	0.738	-0.093
102	0	Correlation	0.825	0.825	0
103	0	Correlation	0.829	0.829	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.825	0.827	0.829	0.0028284	0.825	0.827	0.829	0.0028284	0	0	0	0
50	0.822	0.82914	0.837	0.005305	0.775	0.791	0.806	0.01052	-0.052	-0.038143	-0.028	0.011187
100	0.827	0.83267	0.837	0.0036697	0.738	0.75517	0.775	0.016412	-0.093	-0.0775	-0.06	0.017026

Device Test: 6.154 START_DLY(T_start/IN//12/0/0/0/@START_DLY)





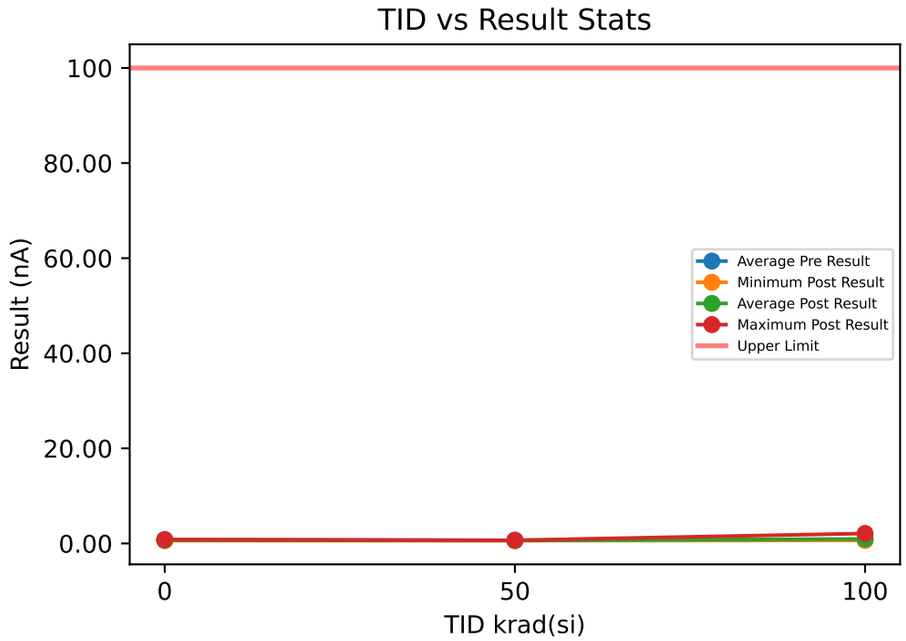
Test Results (Upper Limit = 2.8 ())

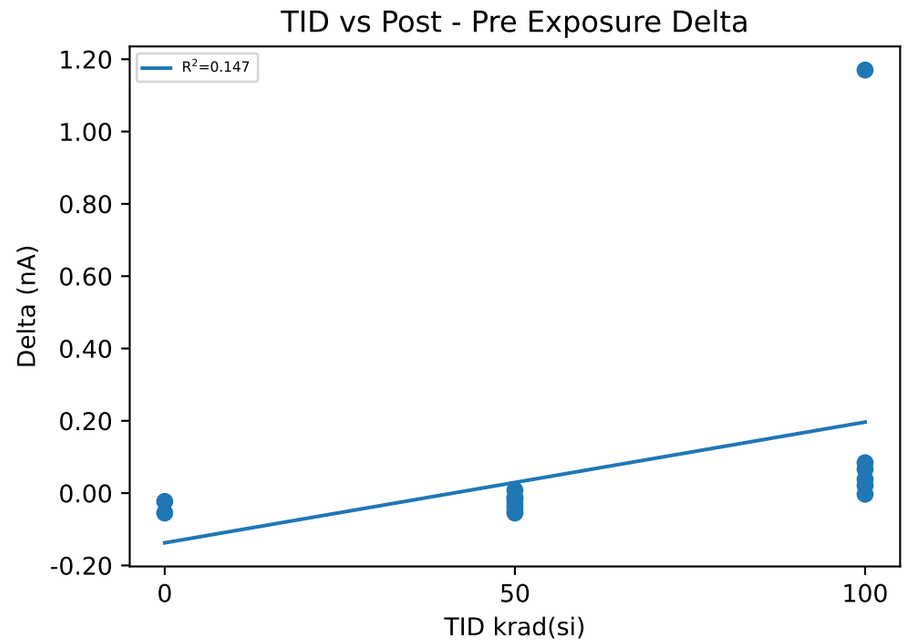
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.245	0.26	0.015
89	50	Biased	0.255	0.261	0.006
90	50	Biased	0.275	0.276	0.001
92	50	Biased	0.282	0.269	-0.013
93	50	Unbiased	0.273	0.277	0.004
94	50	Unbiased	0.209	0.228	0.019
95	50	Unbiased	0.2	0.23	0.03
96	100	Biased	0.286	0.276	-0.01
97	100	Biased	0.279	0.288	0.009
98	100	Biased	0.275	0.285	0.01
99	100	Unbiased	0.263	0.28	0.017
100	100	Unbiased	0.206	0.265	0.059
101	100	Unbiased	0.206	0.245	0.039
102	0	Correlation	0.196	0.208	0.012
103	0	Correlation	0.287	0.281	-0.006

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.196	0.2415	0.287	0.064347	0.208	0.2445	0.281	0.051619	-0.006	0.003	0.012	0.012728
50	0.2	0.24843	0.282	0.032639	0.228	0.25729	0.277	0.02041	-0.013	0.0088571	0.03	0.013898
100	0.206	0.2525	0.286	0.036785	0.245	0.27317	0.288	0.015968	-0.01	0.020667	0.059	0.024533

Device Test: 6.16 ILKG_SR_UVLO(ILKG_SR_UVLOb/SR_UVLOb//14/0/0/0/@ILKG_SR_UVLO)





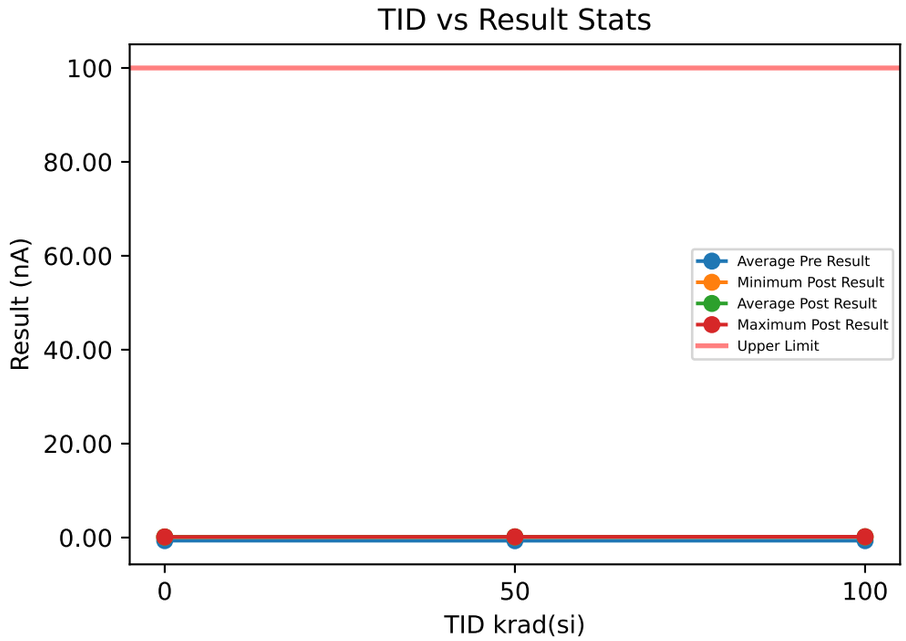
Test Results (Upper Limit = 100.0 (nA))

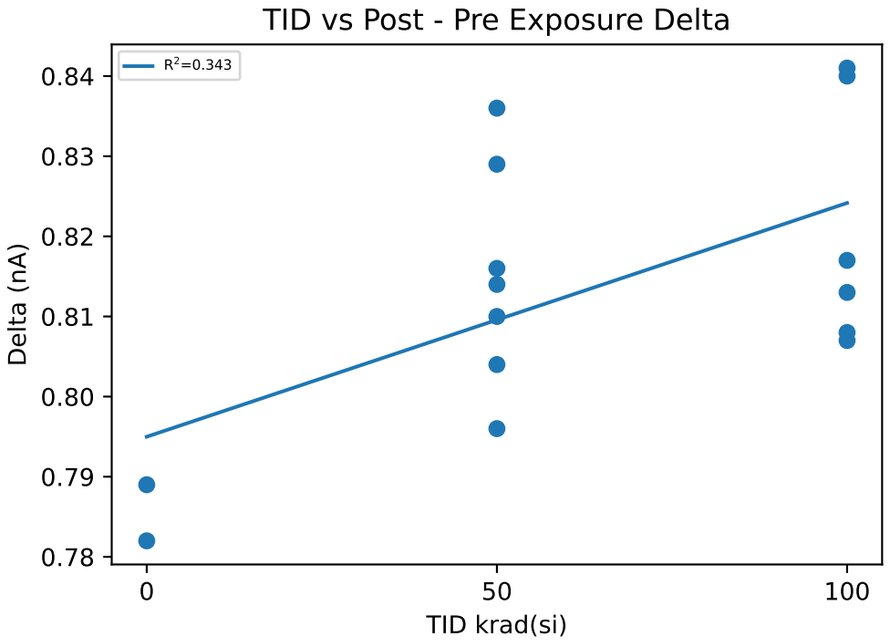
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.67	0.615	-0.055
89	50	Biased	0.628	0.601	-0.027
90	50	Biased	0.658	0.643	-0.015
92	50	Biased	0.621	0.584	-0.037
93	50	Unbiased	0.633	0.621	-0.012
94	50	Unbiased	0.666	0.674	0.008
95	50	Unbiased	0.654	0.605	-0.049
96	100	Biased	0.927	2.097	1.17
97	100	Biased	0.612	0.65	0.038
98	100	Biased	0.598	0.682	0.084
99	100	Unbiased	0.597	0.663	0.066
100	100	Unbiased	0.94	0.961	0.021
101	100	Unbiased	0.648	0.645	-0.003
102	0	Correlation	0.885	0.83	-0.055
103	0	Correlation	0.598	0.575	-0.023

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.598	0.7415	0.885	0.20294	0.575	0.7025	0.83	0.18031	-0.055	-0.039	-0.023	0.022627
50	0.621	0.64714	0.67	0.019548	0.584	0.62043	0.674	0.029866	-0.055	-0.026714	0.008	0.022216
100	0.597	0.72033	0.94	0.1662	0.645	0.94967	2.097	0.57497	-0.003	0.22933	1.17	0.46188

Device Test: 6.17 ILKG_SENSE(ILKG_SENSE1/SENSE1//3/0/0/0/@ILKG_SENSE)





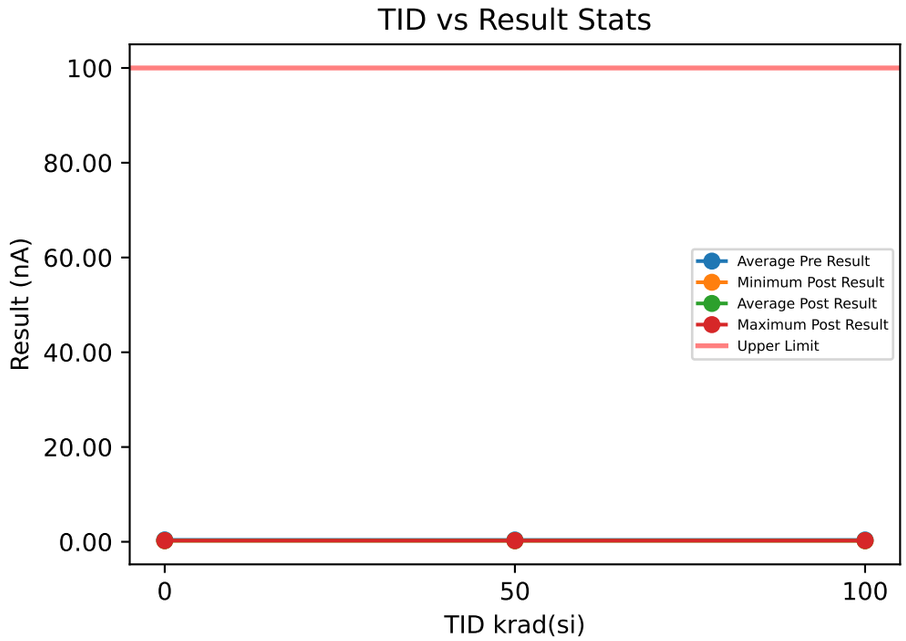
Test Results (Upper Limit = 100.0 (nA))

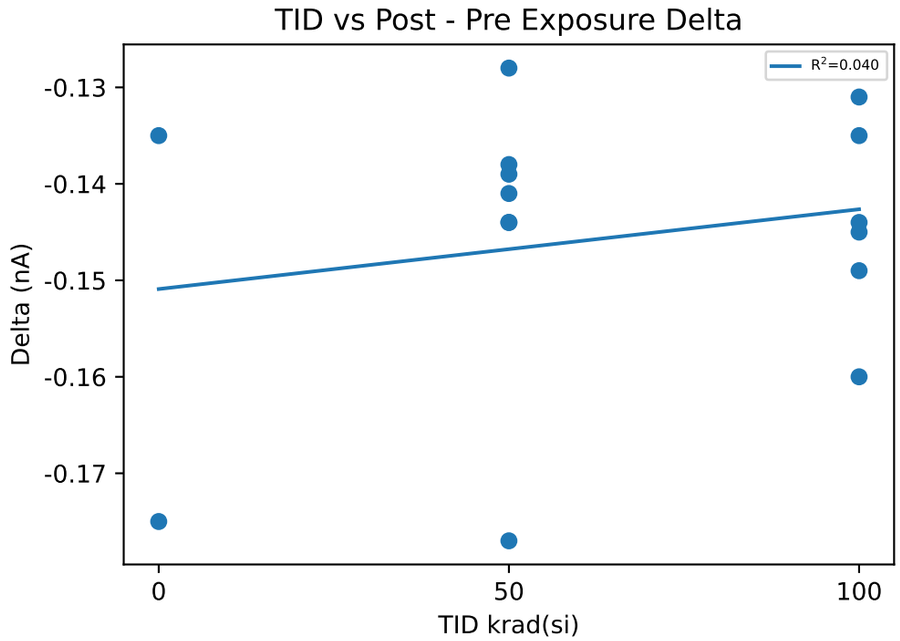
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	-0.659	0.137	0.796
89	50	Biased	-0.676	0.14	0.816
90	50	Biased	-0.668	0.142	0.81
92	50	Biased	-0.686	0.15	0.836
93	50	Unbiased	-0.699	0.13	0.829
94	50	Unbiased	-0.666	0.138	0.804
95	50	Unbiased	-0.676	0.138	0.814
96	100	Biased	-0.66	0.157	0.817
97	100	Biased	-0.674	0.167	0.841
98	100	Biased	-0.672	0.141	0.813
99	100	Unbiased	-0.667	0.173	0.84
100	100	Unbiased	-0.661	0.147	0.808
101	100	Unbiased	-0.663	0.144	0.807
102	0	Correlation	-0.66	0.129	0.789
103	0	Correlation	-0.661	0.121	0.782

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.661	-0.6605	-0.66	0.00070711	0.121	0.125	0.129	0.0056569	0.782	0.7855	0.789	0.0049497
50	-0.699	-0.67571	-0.659	0.013425	0.13	0.13929	0.15	0.0060198	0.796	0.815	0.836	0.01382
100	-0.674	-0.66617	-0.66	0.0058452	0.141	0.15483	0.173	0.01306	0.807	0.821	0.841	0.015531

Device Test: 6.18 ILKG_SENSE(ILKG_SENSE2/SENSE2//3/0/0/0/@ILKG_SENSE)





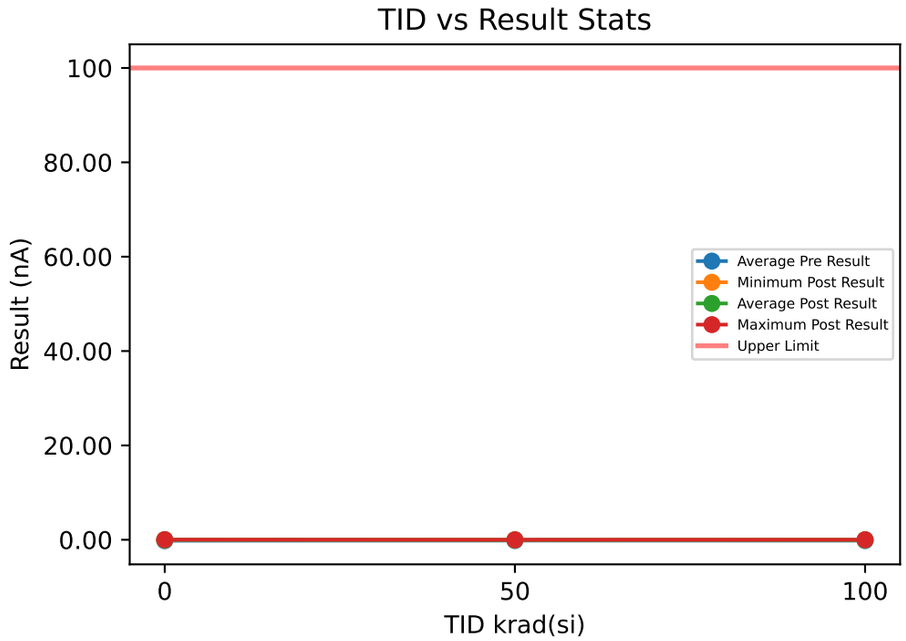
Test Results (Upper Limit = 100.0 (nA))

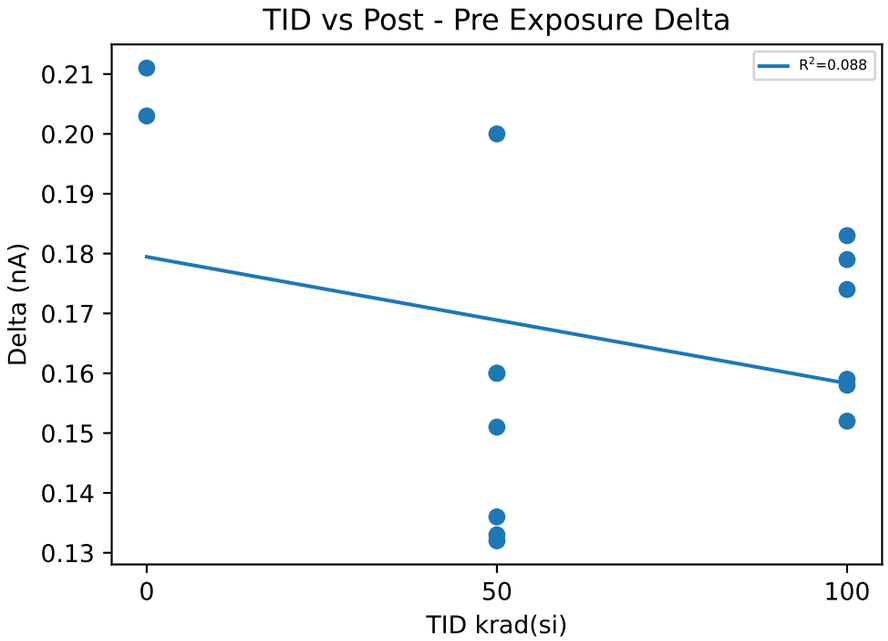
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.38	0.236	-0.144
89	50	Biased	0.373	0.229	-0.144
90	50	Biased	0.385	0.247	-0.138
92	50	Biased	0.374	0.246	-0.128
93	50	Unbiased	0.38	0.239	-0.141
94	50	Unbiased	0.375	0.236	-0.139
95	50	Unbiased	0.409	0.232	-0.177
96	100	Biased	0.393	0.244	-0.149
97	100	Biased	0.398	0.253	-0.145
98	100	Biased	0.384	0.224	-0.16
99	100	Unbiased	0.373	0.229	-0.144
100	100	Unbiased	0.373	0.238	-0.135
101	100	Unbiased	0.372	0.241	-0.131
102	0	Correlation	0.389	0.254	-0.135
103	0	Correlation	0.409	0.234	-0.175

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.389	0.399	0.409	0.014142	0.234	0.244	0.254	0.014142	-0.175	-0.155	-0.135	0.028284
50	0.373	0.38229	0.409	0.012513	0.229	0.23786	0.247	0.0067188	-0.177	-0.14443	-0.128	0.01535
100	0.372	0.38217	0.398	0.011339	0.224	0.23817	0.253	0.010458	-0.16	-0.144	-0.131	0.010315

Device Test: 6.19 ILKG_SENSE(ILKG_SENSE3/SENSE3//3/0/0/0/@ILKG_SENSE)





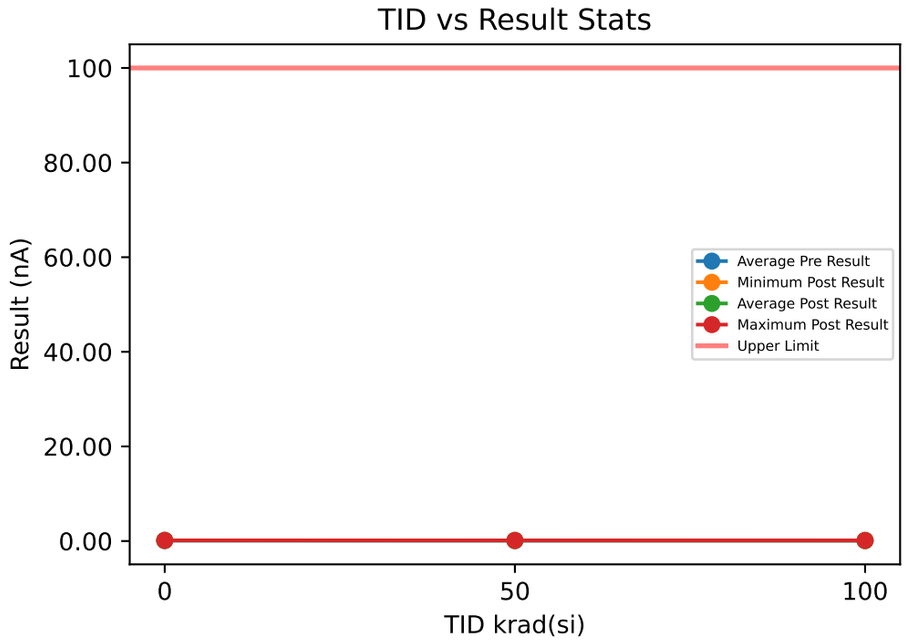
Test Results (Upper Limit = 100.0 (nA))

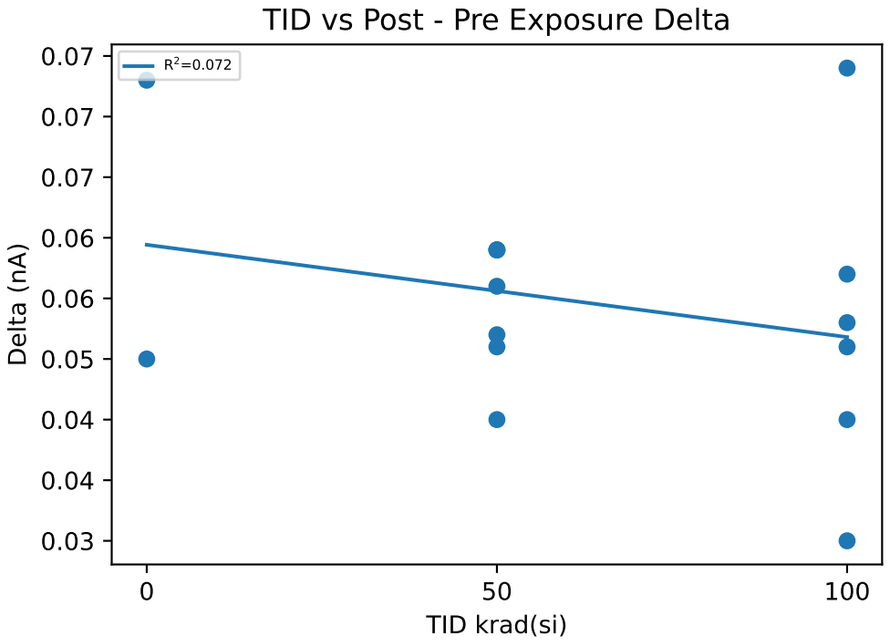
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	-0.179	-0.028	0.151
89	50	Biased	-0.157	-0.021	0.136
90	50	Biased	-0.155	-0.023	0.132
92	50	Biased	-0.158	-0.025	0.133
93	50	Unbiased	-0.164	-0.004	0.16
94	50	Unbiased	-0.214	-0.014	0.2
95	50	Unbiased	-0.183	-0.023	0.16
96	100	Biased	-0.2	-0.026	0.174
97	100	Biased	-0.201	-0.018	0.183
98	100	Biased	-0.174	-0.016	0.158
99	100	Unbiased	-0.17	-0.018	0.152
100	100	Unbiased	-0.18	-0.021	0.159
101	100	Unbiased	-0.169	0.01	0.179
102	0	Correlation	-0.219	-0.016	0.203
103	0	Correlation	-0.184	0.027	0.211

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.219	-0.2015	-0.184	0.024749	-0.016	0.0055	0.027	0.030406	0.203	0.207	0.211	0.0056569
50	-0.214	-0.17286	-0.155	0.021224	-0.028	-0.019714	-0.004	0.0081591	0.132	0.15314	0.2	0.023947
100	-0.201	-0.18233	-0.169	0.014597	-0.026	-0.014833	0.01	0.012656	0.152	0.1675	0.183	0.012787

Device Test: 6.20 ILKG_SENSE(ILKG_SENSE4/SENSE4//3/0/0/0/@ILKG_SENSE)





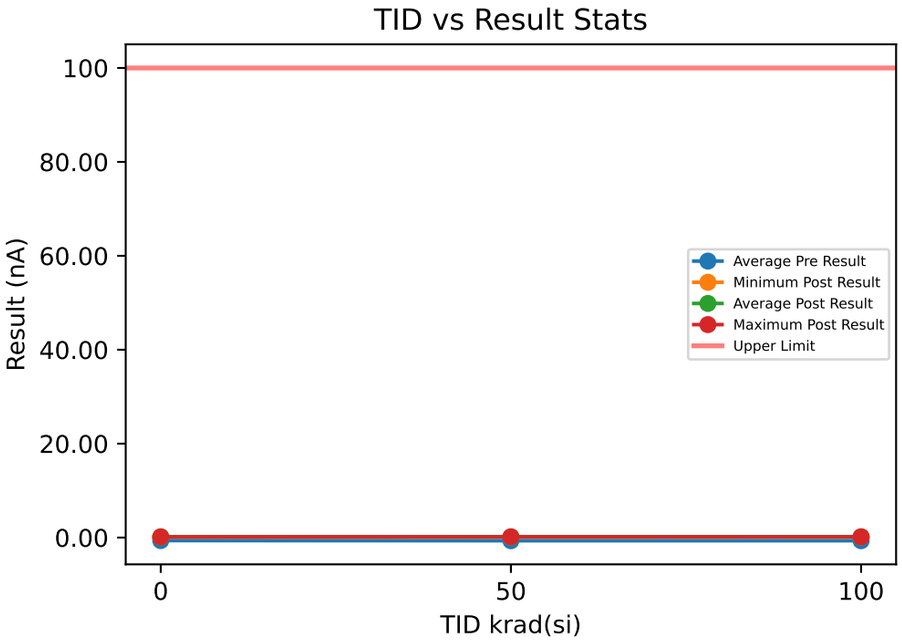
Test Results (Upper Limit = 100.0 (nA))

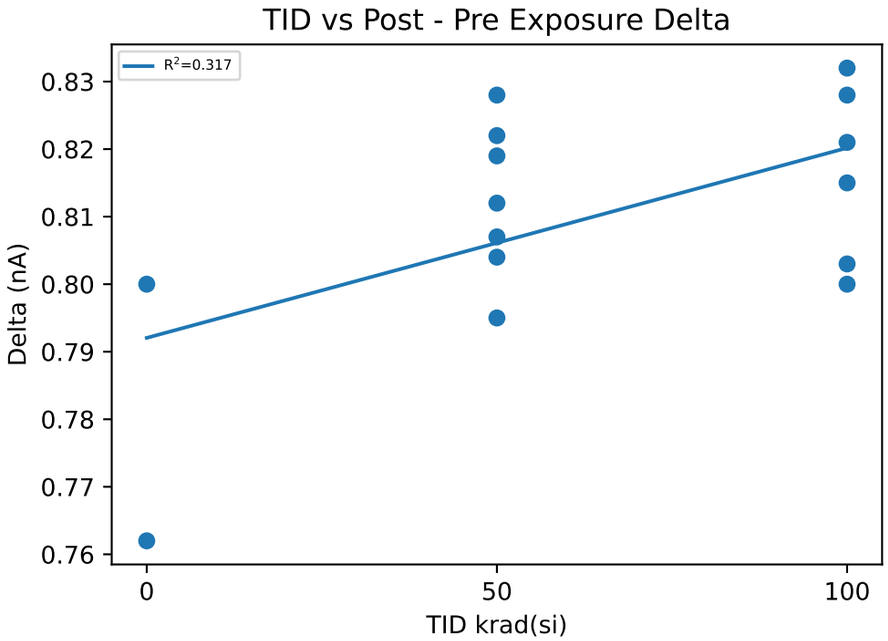
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.07	0.122	0.052
89	50	Biased	0.075	0.134	0.059
90	50	Biased	0.072	0.131	0.059
92	50	Biased	0.074	0.119	0.045
93	50	Unbiased	0.077	0.128	0.051
94	50	Unbiased	0.066	0.125	0.059
95	50	Unbiased	0.065	0.121	0.056
96	100	Biased	0.083	0.136	0.053
97	100	Biased	0.058	0.115	0.057
98	100	Biased	0.06	0.134	0.074
99	100	Unbiased	0.075	0.126	0.051
100	100	Unbiased	0.058	0.103	0.045
101	100	Unbiased	0.073	0.108	0.035
102	0	Correlation	0.077	0.15	0.073
103	0	Correlation	0.074	0.124	0.05

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.074	0.0755	0.077	0.0021213	0.124	0.137	0.15	0.018385	0.05	0.0615	0.073	0.016263
50	0.065	0.071286	0.077	0.0045356	0.119	0.12571	0.134	0.0055291	0.045	0.054429	0.059	0.0053497
100	0.058	0.067833	0.083	0.01061	0.103	0.12033	0.136	0.01375	0.035	0.0525	0.074	0.013019

Device Test: 6.21 ILKG_SENSE(ILKG_SENSE1/SENSE1//14/0/0/0/@ILKG_SENSE)





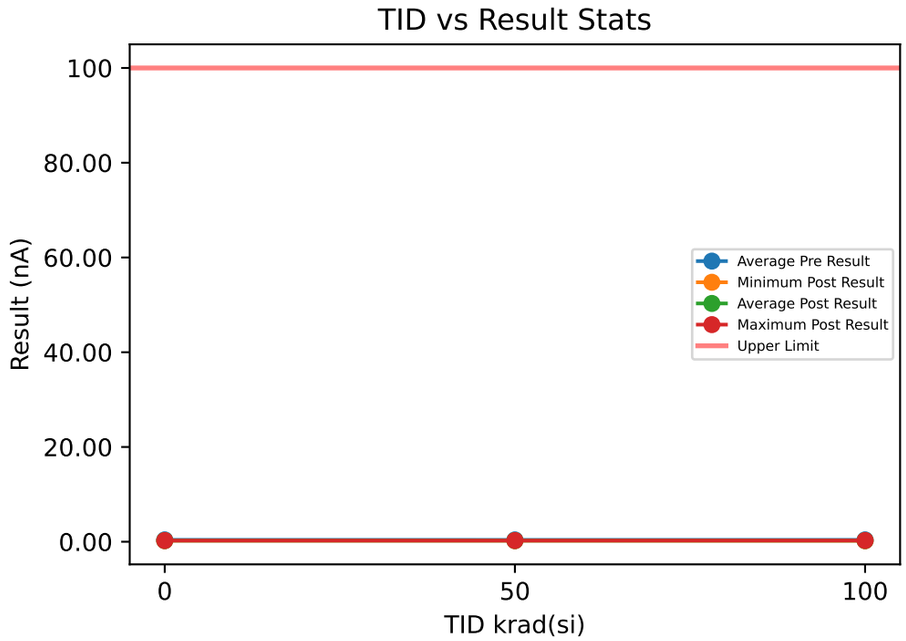
Test Results (Upper Limit = 100.0 (nA))

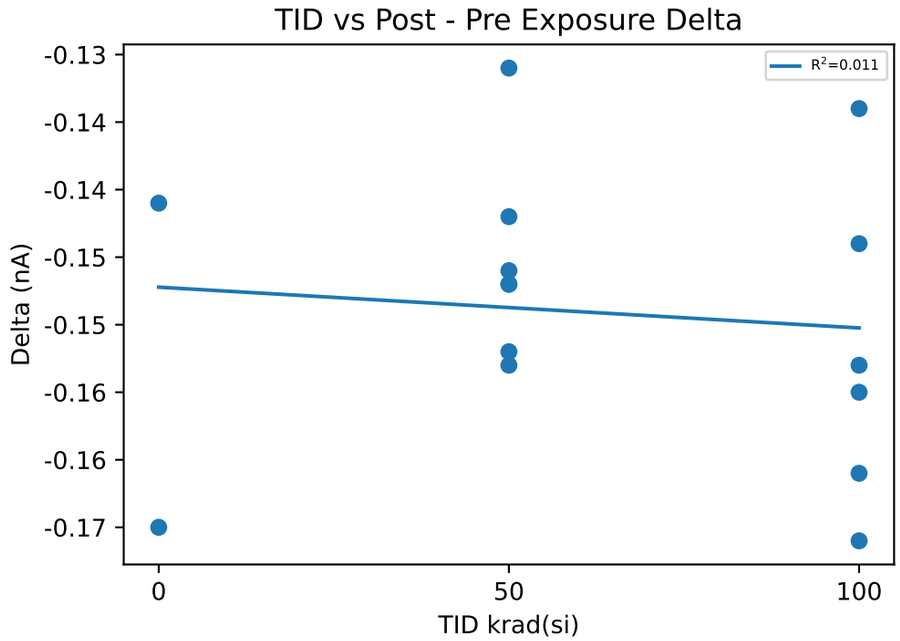
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	-0.676	0.143	0.819
89	50	Biased	-0.654	0.141	0.795
90	50	Biased	-0.658	0.149	0.807
92	50	Biased	-0.675	0.153	0.828
93	50	Unbiased	-0.687	0.135	0.822
94	50	Unbiased	-0.677	0.135	0.812
95	50	Unbiased	-0.666	0.138	0.804
96	100	Biased	-0.67	0.151	0.821
97	100	Biased	-0.662	0.141	0.803
98	100	Biased	-0.68	0.152	0.832
99	100	Unbiased	-0.666	0.149	0.815
100	100	Unbiased	-0.678	0.15	0.828
101	100	Unbiased	-0.655	0.145	0.8
102	0	Correlation	-0.655	0.145	0.8
103	0	Correlation	-0.626	0.136	0.762

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.655	-0.6405	-0.626	0.020506	0.136	0.1405	0.145	0.006364	0.762	0.781	0.8	0.02687
50	-0.687	-0.67043	-0.654	0.011646	0.135	0.142	0.153	0.0069041	0.795	0.81243	0.828	0.011414
100	-0.68	-0.6685	-0.655	0.0095446	0.141	0.148	0.152	0.0041952	0.8	0.8165	0.832	0.013035

Device Test: 6.22 ILKG_SENSE(ILKG_SENSE2/SENSE2//14/0/0/0/@ILKG_SENSE)





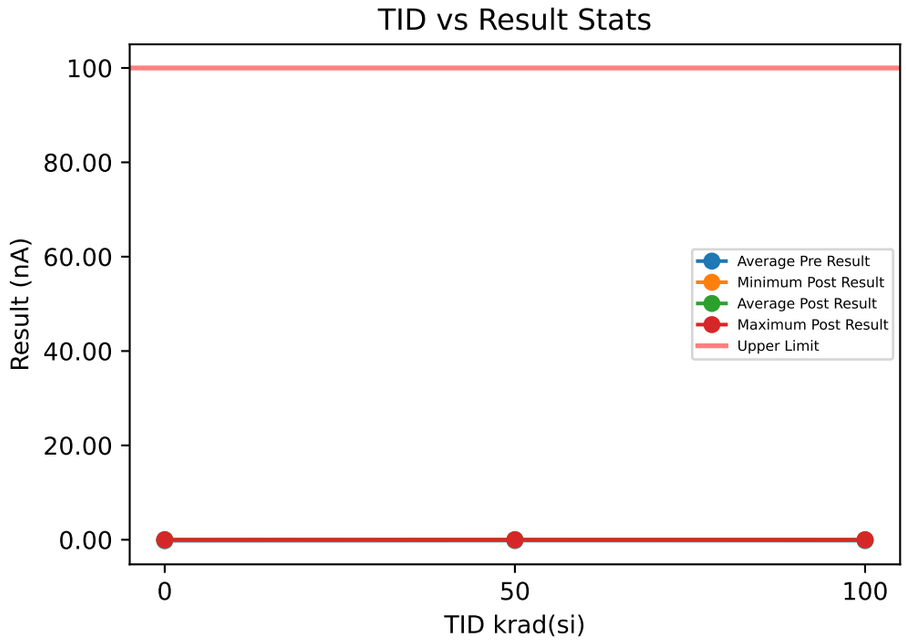
Test Results (Upper Limit = 100.0 (nA))

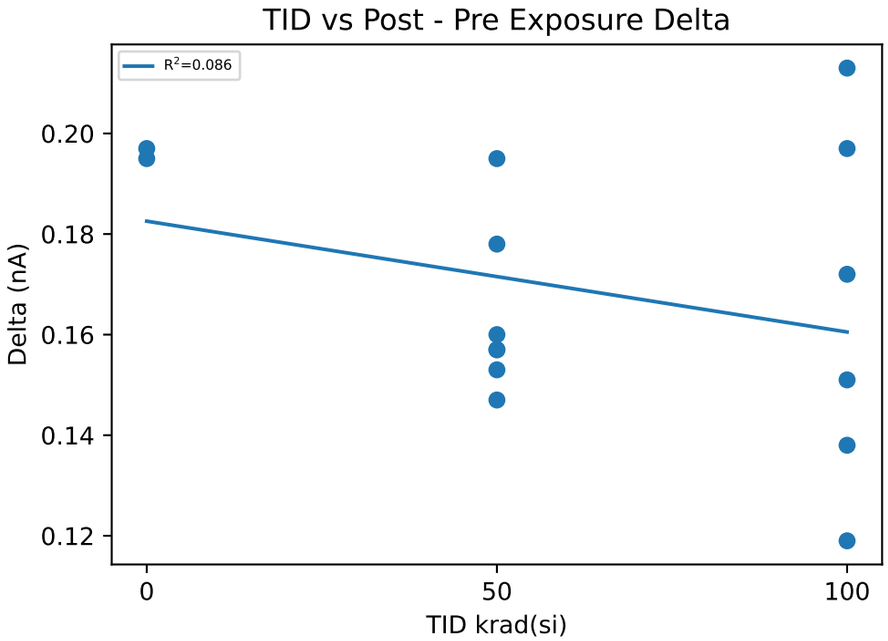
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.379	0.232	-0.147
89	50	Biased	0.386	0.244	-0.142
90	50	Biased	0.388	0.241	-0.147
92	50	Biased	0.387	0.235	-0.152
93	50	Unbiased	0.373	0.242	-0.131
94	50	Unbiased	0.392	0.246	-0.146
95	50	Unbiased	0.396	0.243	-0.153
96	100	Biased	0.399	0.255	-0.144
97	100	Biased	0.392	0.258	-0.134
98	100	Biased	0.388	0.227	-0.161
99	100	Unbiased	0.379	0.213	-0.166
100	100	Unbiased	0.404	0.249	-0.155
101	100	Unbiased	0.388	0.235	-0.153
102	0	Correlation	0.386	0.245	-0.141
103	0	Correlation	0.399	0.234	-0.165

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.386	0.3925	0.399	0.0091924	0.234	0.2395	0.245	0.0077782	-0.165	-0.153	-0.141	0.016971
50	0.373	0.38586	0.396	0.0077337	0.232	0.24043	0.246	0.0050615	-0.153	-0.14543	-0.131	0.0073679
100	0.379	0.39167	0.404	0.0088694	0.213	0.2395	0.258	0.017615	-0.166	-0.15217	-0.134	0.011618

Device Test: 6.23 ILKG_SENSE(ILKG_SENSE3/SENSE3//14/0/0/0/@ILKG_SENSE)





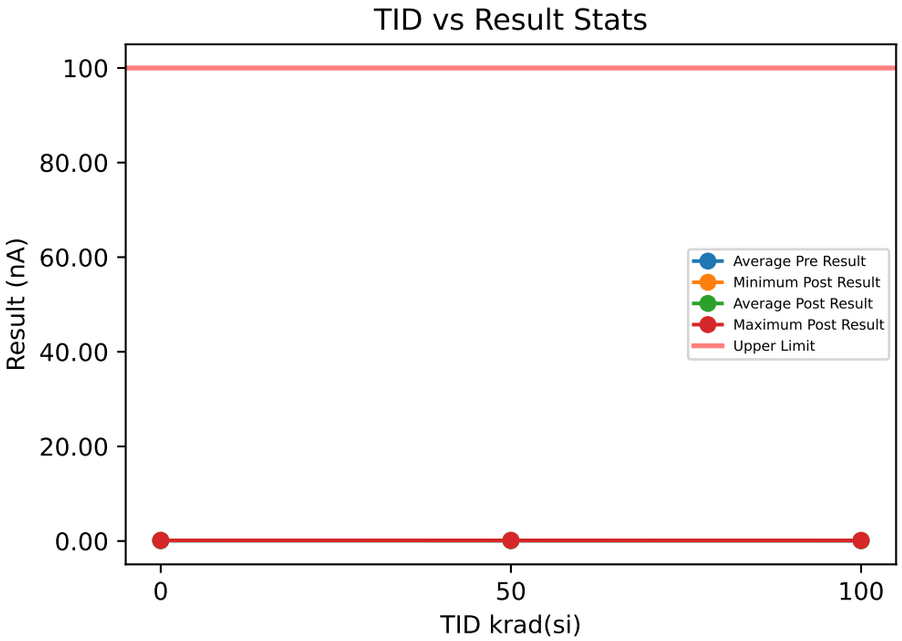
Test Results (Upper Limit = 100.0 (nA))

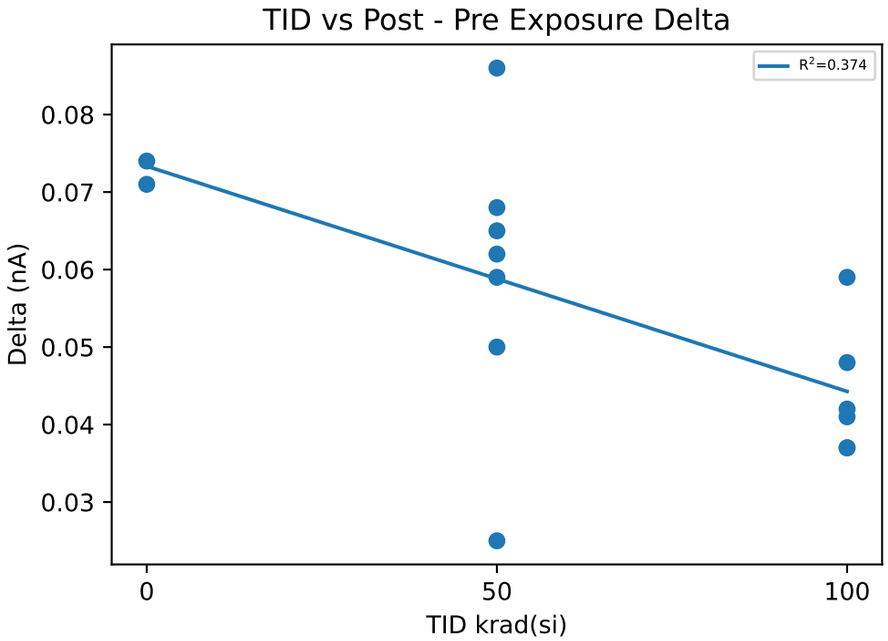
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	-0.186	-0.026	0.16
89	50	Biased	-0.154	-0.001	0.153
90	50	Biased	-0.185	-0.007	0.178
92	50	Biased	-0.2	-0.005	0.195
93	50	Unbiased	-0.182	-0.025	0.157
94	50	Unbiased	-0.151	0.006	0.157
95	50	Unbiased	-0.164	-0.017	0.147
96	100	Biased	-0.24	-0.027	0.213
97	100	Biased	-0.222	-0.025	0.197
98	100	Biased	-0.18	-0.008	0.172
99	100	Unbiased	-0.147	-0.028	0.119
100	100	Unbiased	-0.155	-0.004	0.151
101	100	Unbiased	-0.16	-0.022	0.138
102	0	Correlation	-0.195	0	0.195
103	0	Correlation	-0.217	-0.02	0.197

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.217	-0.206	-0.195	0.015556	-0.02	-0.01	0	0.014142	0.195	0.196	0.197	0.0014142
50	-0.2	-0.17457	-0.151	0.018402	-0.026	-0.010714	0.006	0.01223	0.147	0.16386	0.195	0.016737
100	-0.24	-0.184	-0.147	0.038424	-0.028	-0.019	-0.004	0.010354	0.119	0.165	0.213	0.035827

Device Test: 6.24 ILKG_SENSE(ILKG_SENSE4/SENSE4//14/0/0/0/@ILKG_SENSE)





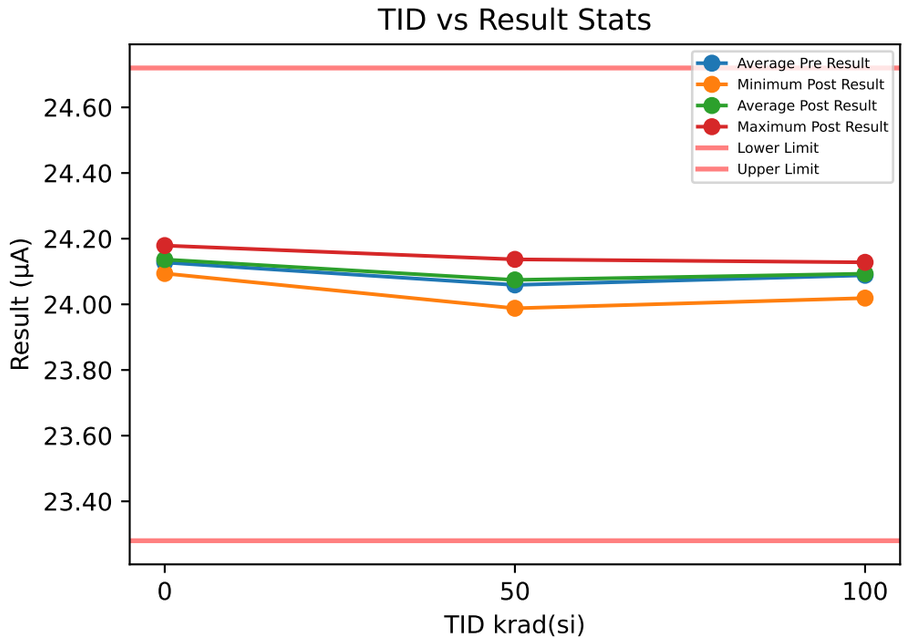
Test Results (Upper Limit = 100.0 (nA))

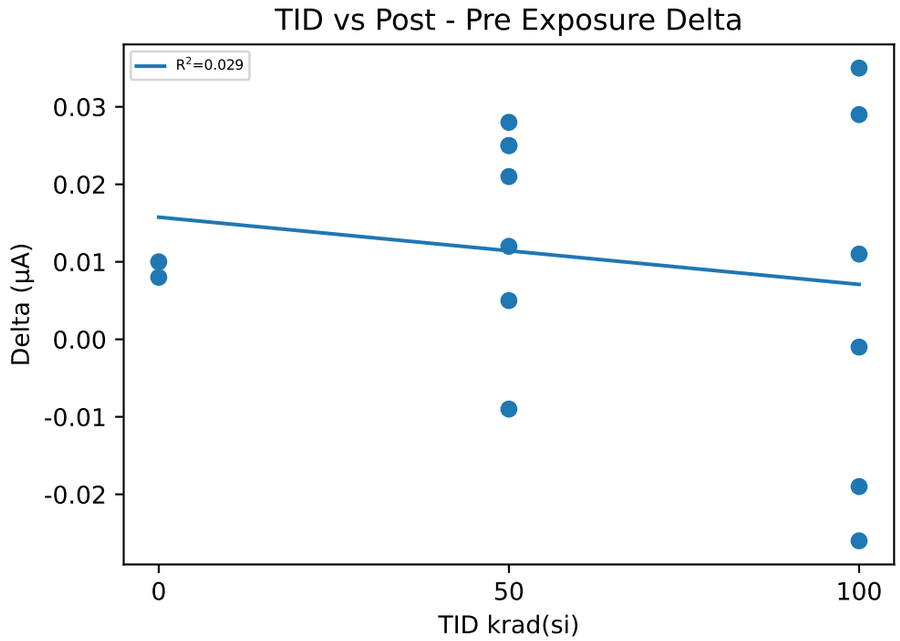
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.059	0.118	0.059
89	50	Biased	0.046	0.132	0.086
90	50	Biased	0.099	0.124	0.025
92	50	Biased	0.061	0.129	0.068
93	50	Unbiased	0.063	0.113	0.05
94	50	Unbiased	0.07	0.132	0.062
95	50	Unbiased	0.072	0.137	0.065
96	100	Biased	0.051	0.11	0.059
97	100	Biased	0.08	0.121	0.041
98	100	Biased	0.077	0.119	0.042
99	100	Unbiased	0.071	0.108	0.037
100	100	Unbiased	0.064	0.112	0.048
101	100	Unbiased	0.071	0.108	0.037
102	0	Correlation	0.069	0.14	0.071
103	0	Correlation	0.059	0.133	0.074

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.059	0.064	0.069	0.0070711	0.133	0.1365	0.14	0.0049497	0.071	0.0725	0.074	0.0021213
50	0.046	0.067143	0.099	0.016406	0.113	0.12643	0.137	0.0085412	0.025	0.059286	0.086	0.01867
100	0.051	0.069	0.08	0.010412	0.108	0.113	0.121	0.0056569	0.037	0.044	0.059	0.0083905

Device Test: 6.25 IHYS(IHYS_SENSE1/SENSE1//3/0/0/0/@IHYS)





Test Results (Lower Limit = 23.28, Upper Limit = 24.72 (µA))

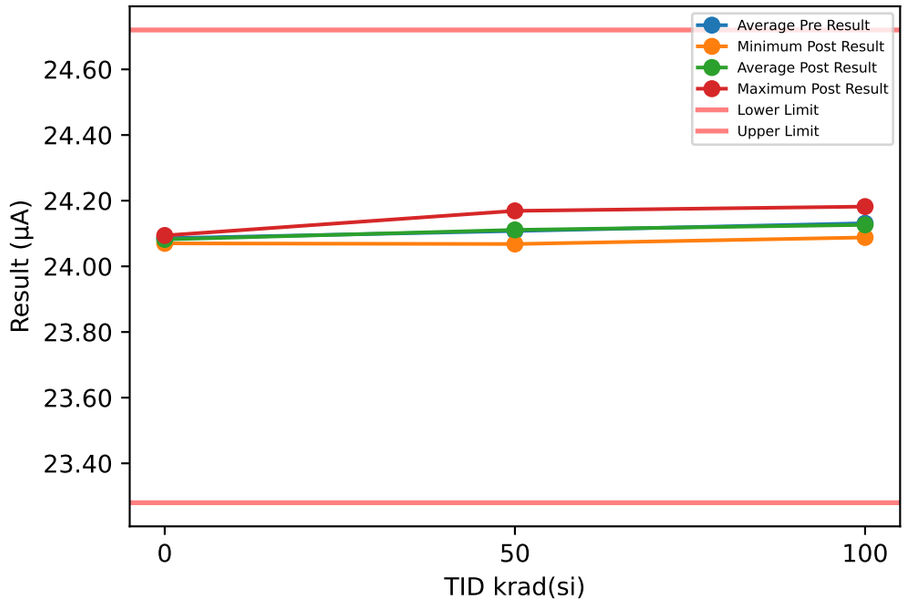
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.986	24.014	0.028
89	50	Biased	23.983	23.988	0.005
90	50	Biased	24.064	24.089	0.025
92	50	Biased	24.09	24.081	-0.009
93	50	Unbiased	24.116	24.137	0.021
94	50	Unbiased	24.08	24.105	0.025
95	50	Unbiased	24.095	24.107	0.012
96	100	Biased	24.112	24.086	-0.026
97	100	Biased	24.129	24.128	-0.001
98	100	Biased	24.093	24.104	0.011
99	100	Unbiased	24.077	24.112	0.035
100	100	Unbiased	23.99	24.019	0.029
101	100	Unbiased	24.13	24.111	-0.019
102	0	Correlation	24.086	24.094	0.008
103	0	Correlation	24.169	24.179	0.01

Test Statistics (µA)

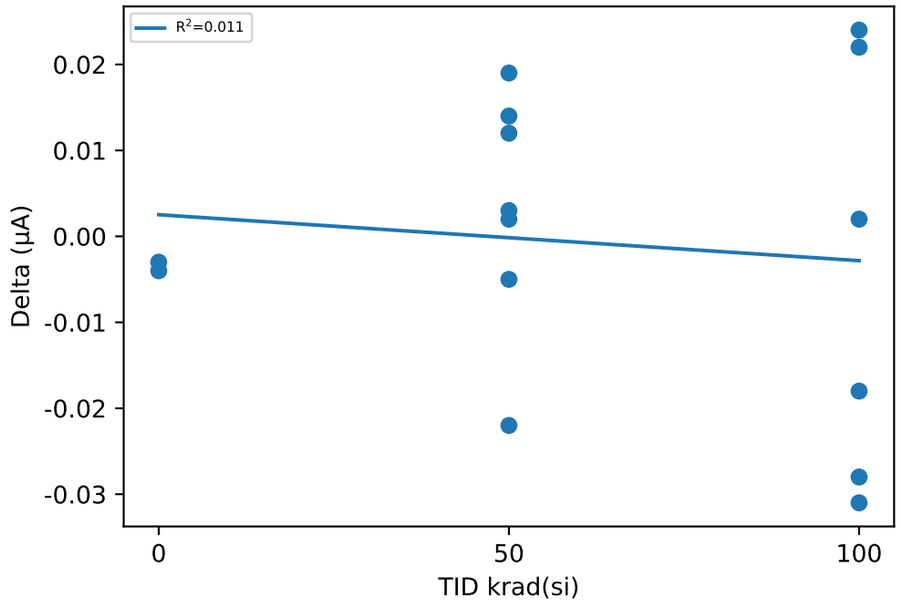
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.086	24.127	24.169	0.05869	24.094	24.136	24.179	0.060104	0.008	0.009	0.01	0.0014142
50	23.983	24.059	24.116	0.053349	23.988	24.074	24.137	0.053678	-0.009	0.015286	0.028	0.013475
100	23.99	24.088	24.13	0.052478	24.019	24.093	24.128	0.038872	-0.026	0.0048333	0.035	0.024839

Device Test: 6.26 IHYS(IHYS_SENSE2/SENSE2//3/0/0/0/@IHYS)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 23.28, Upper Limit = 24.72 (µA))

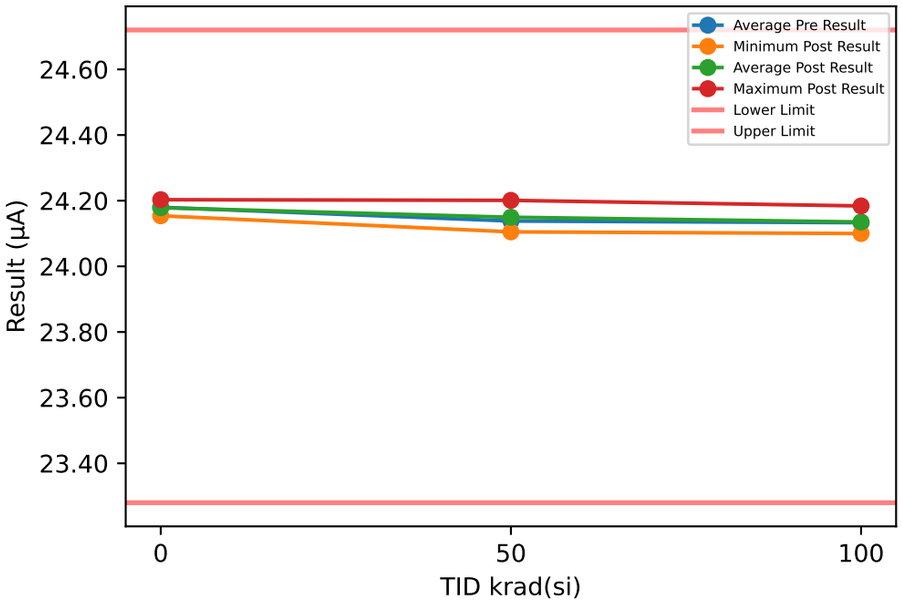
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	24.071	24.09	0.019
89	50	Biased	24.073	24.068	-0.005
90	50	Biased	24.101	24.115	0.014
92	50	Biased	24.191	24.169	-0.022
93	50	Unbiased	24.107	24.11	0.003
94	50	Unbiased	24.106	24.118	0.012
95	50	Unbiased	24.105	24.107	0.002
96	100	Biased	24.136	24.105	-0.031
97	100	Biased	24.2	24.182	-0.018
98	100	Biased	24.168	24.17	0.002
99	100	Unbiased	24.077	24.099	0.022
100	100	Unbiased	24.064	24.088	0.024
101	100	Unbiased	24.142	24.114	-0.028
102	0	Correlation	24.098	24.094	-0.004
103	0	Correlation	24.073	24.07	-0.003

Test Statistics (µA)

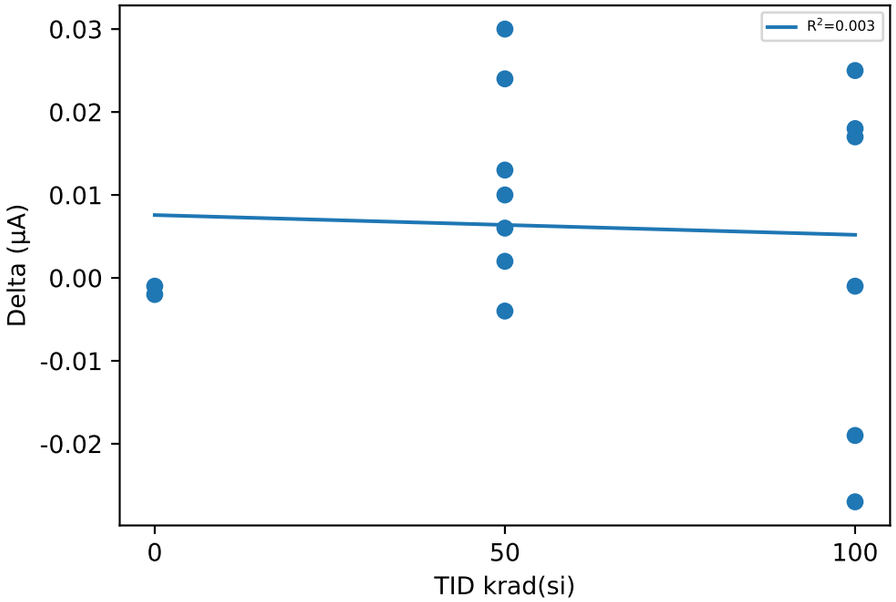
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.073	24.085	24.098	0.017678	24.07	24.082	24.094	0.016971	-0.004	-0.0035	-0.003	0.00070711
50	24.071	24.108	24.191	0.039886	24.068	24.111	24.169	0.030919	-0.022	0.0032857	0.019	0.013829
100	24.064	24.131	24.2	0.052308	24.088	24.126	24.182	0.039571	-0.031	-0.0048333	0.024	0.024466

Device Test: 6.27 IHYS(IHYS_SENSE3/SENSE3//3/0/0/0/@IHYS)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 23.28, Upper Limit = 24.72 (µA))

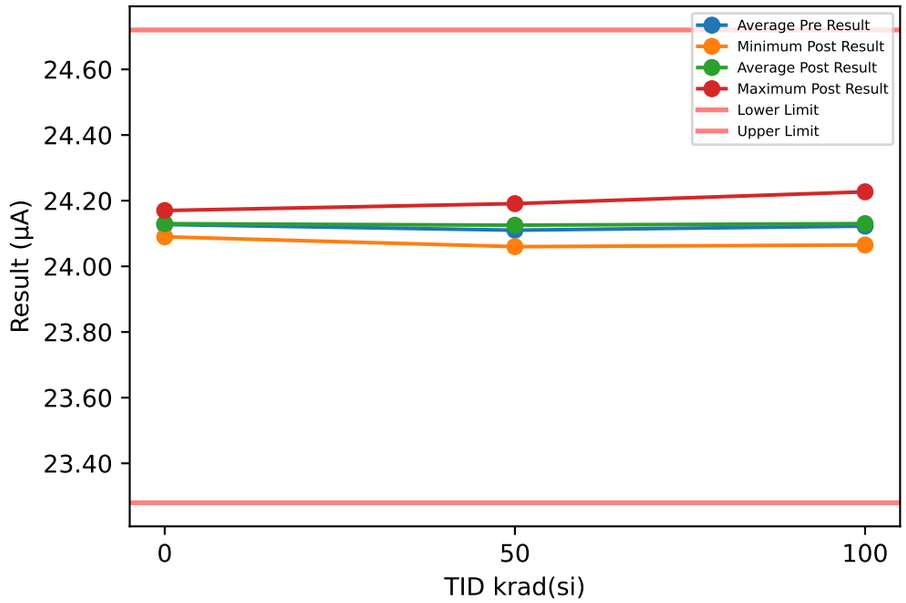
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	24.096	24.126	0.03
89	50	Biased	24.099	24.105	0.006
90	50	Biased	24.151	24.175	0.024
92	50	Biased	24.182	24.178	-0.004
93	50	Unbiased	24.139	24.152	0.013
94	50	Unbiased	24.1	24.11	0.01
95	50	Unbiased	24.199	24.201	0.002
96	100	Biased	24.158	24.139	-0.019
97	100	Biased	24.101	24.1	-0.001
98	100	Biased	24.135	24.152	0.017
99	100	Unbiased	24.159	24.184	0.025
100	100	Unbiased	24.106	24.124	0.018
101	100	Unbiased	24.139	24.112	-0.027
102	0	Correlation	24.205	24.203	-0.002
103	0	Correlation	24.155	24.154	-0.001

Test Statistics (µA)

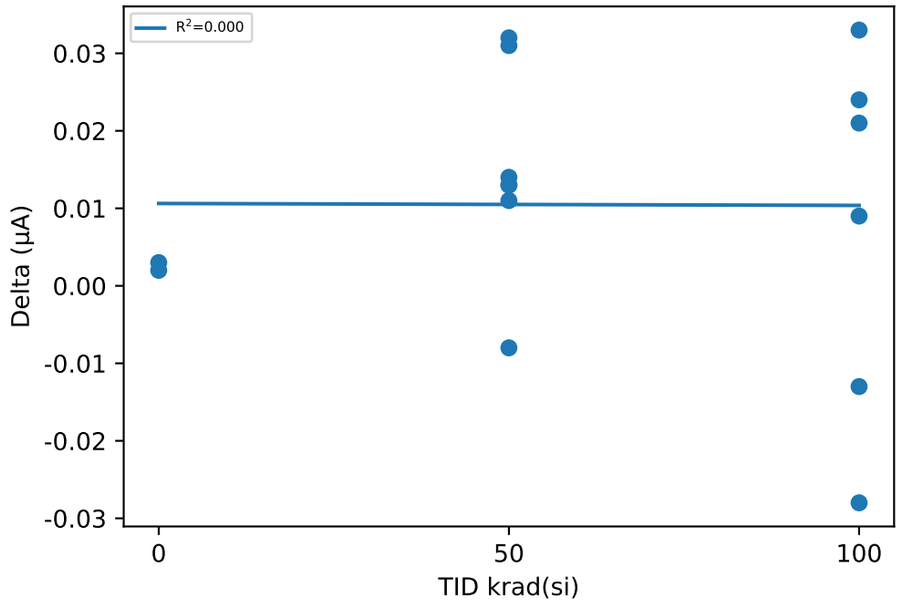
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.155	24.18	24.205	0.035355	24.154	24.178	24.203	0.034648	-0.002	-0.0015	-0.001	0.00070711
50	24.096	24.138	24.199	0.041944	24.105	24.15	24.201	0.036999	-0.004	0.011571	0.03	0.011998
100	24.101	24.133	24.159	0.024876	24.1	24.135	24.184	0.030268	-0.027	0.0021667	0.025	0.021451

Device Test: 6.28 IHYS(IHYS_SENSE4/SENSE4//3/0/0/0/@IHYS)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 23.28, Upper Limit = 24.72 (µA))

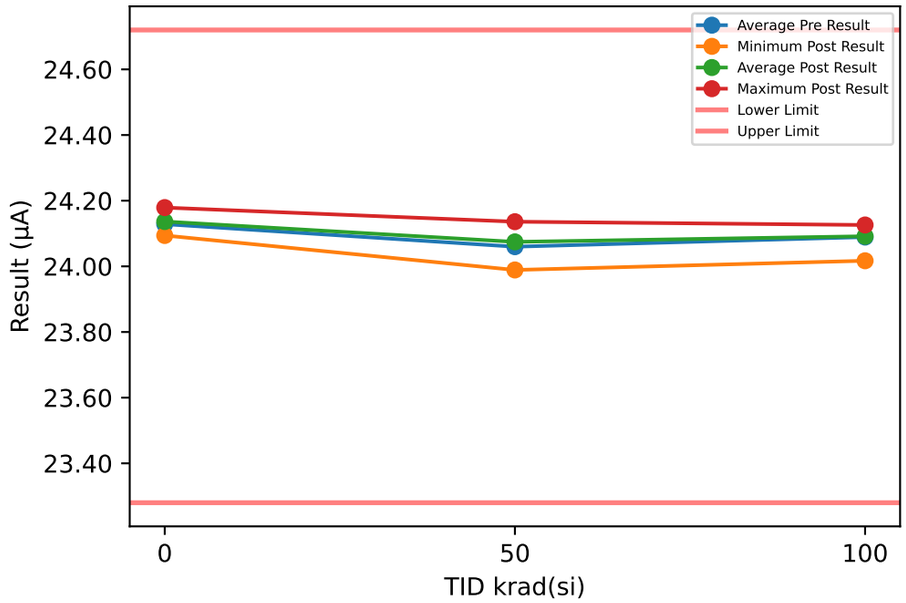
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	24.058	24.089	0.031
89	50	Biased	24.047	24.06	0.013
90	50	Biased	24.159	24.191	0.032
92	50	Biased	24.179	24.171	-0.008
93	50	Unbiased	24.106	24.119	0.013
94	50	Unbiased	24.133	24.147	0.014
95	50	Unbiased	24.089	24.1	0.011
96	100	Biased	24.174	24.161	-0.013
97	100	Biased	24.111	24.12	0.009
98	100	Biased	24.206	24.227	0.021
99	100	Unbiased	24.073	24.106	0.033
100	100	Unbiased	24.078	24.102	0.024
101	100	Unbiased	24.093	24.065	-0.028
102	0	Correlation	24.088	24.09	0.002
103	0	Correlation	24.167	24.17	0.003

Test Statistics (µA)

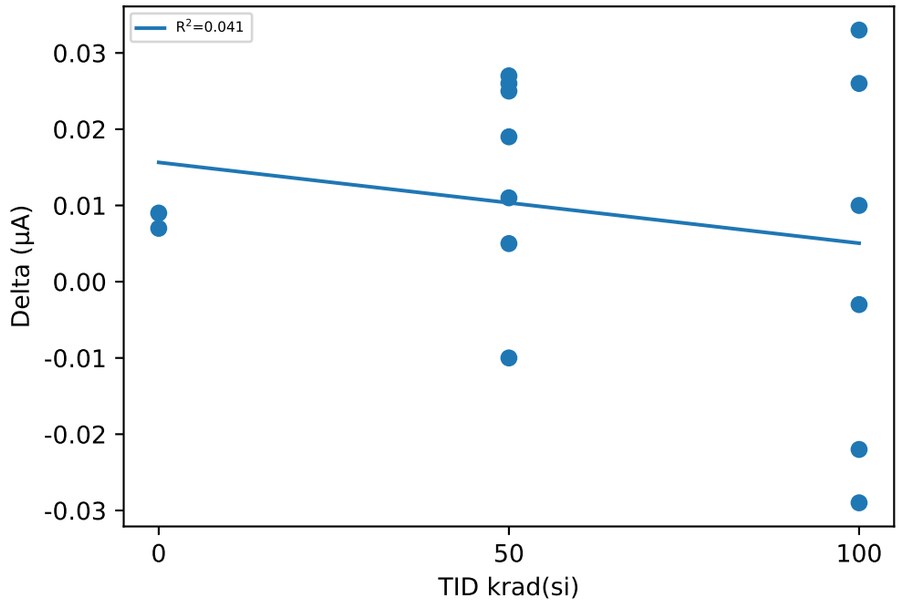
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.088	24.128	24.167	0.055861	24.09	24.13	24.17	0.056569	0.002	0.0025	0.003	0.00070711
50	24.047	24.11	24.179	0.049701	24.06	24.125	24.191	0.046793	-0.008	0.015143	0.032	0.013533
100	24.073	24.123	24.206	0.054877	24.065	24.13	24.227	0.056665	-0.028	0.0076667	0.033	0.023611

Device Test: 6.29 IHYS(IHYS_SENSE1/SENSE1//14/0/0/0/@IHYS)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



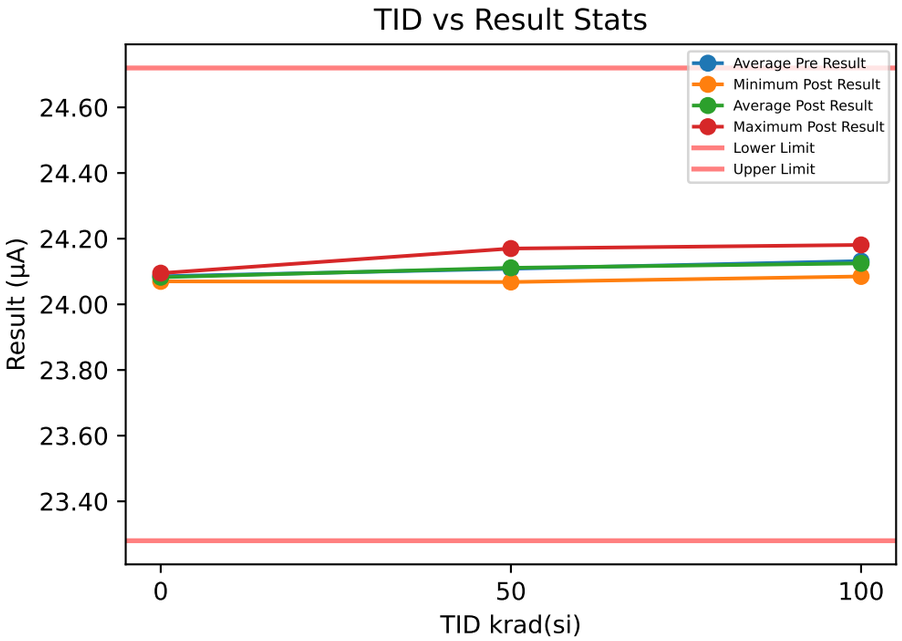
Test Results (Lower Limit = 23.28, Upper Limit = 24.72 (µA))

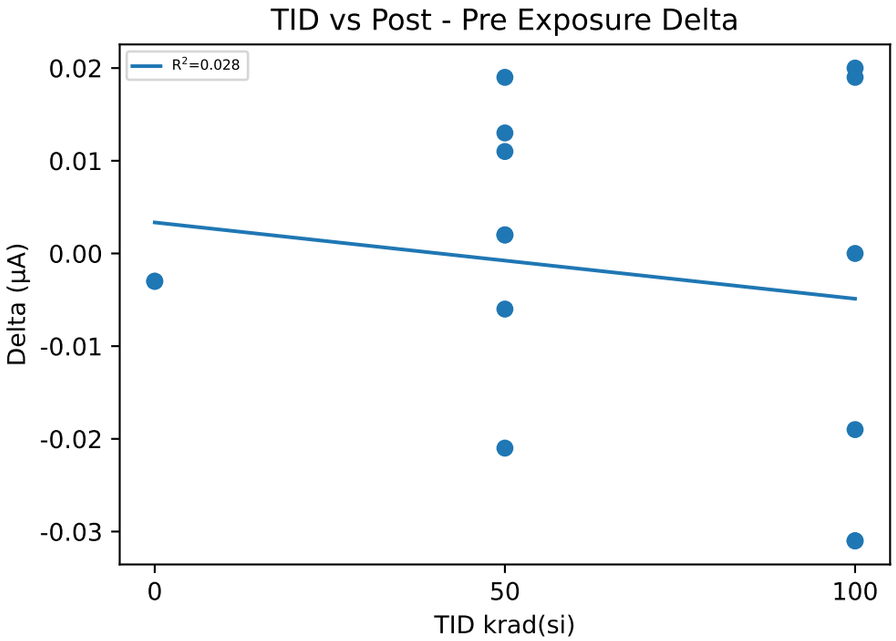
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	23.987	24.014	0.027
89	50	Biased	23.984	23.989	0.005
90	50	Biased	24.064	24.09	0.026
92	50	Biased	24.091	24.081	-0.01
93	50	Unbiased	24.117	24.136	0.019
94	50	Unbiased	24.08	24.105	0.025
95	50	Unbiased	24.096	24.107	0.011
96	100	Biased	24.112	24.083	-0.029
97	100	Biased	24.129	24.126	-0.003
98	100	Biased	24.093	24.103	0.01
99	100	Unbiased	24.078	24.111	0.033
100	100	Unbiased	23.991	24.017	0.026
101	100	Unbiased	24.132	24.11	-0.022
102	0	Correlation	24.087	24.094	0.007
103	0	Correlation	24.17	24.179	0.009

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.087	24.129	24.17	0.05869	24.094	24.136	24.179	0.060104	0.007	0.008	0.009	0.0014142
50	23.984	24.06	24.117	0.053271	23.989	24.075	24.136	0.053263	-0.01	0.014714	0.027	0.013671
100	23.991	24.089	24.132	0.052381	24.017	24.092	24.126	0.03916	-0.029	0.0025	0.033	0.025146

Device Test: 6.30 IHYS(IHYS_SENSE2/SENSE2//14/0/0/0/@IHYS)





Test Results (Lower Limit = 23.28, Upper Limit = 24.72 (µA))

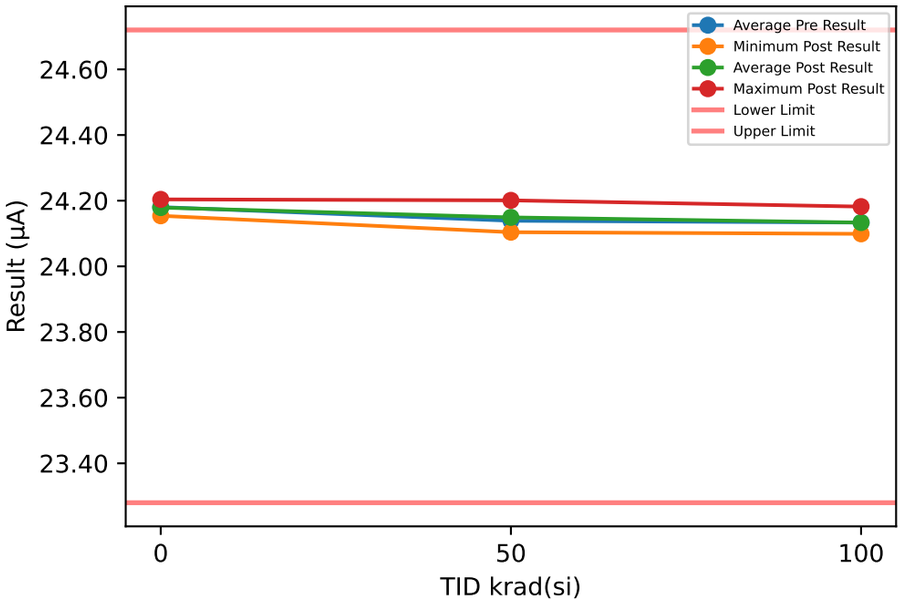
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	24.071	24.09	0.019
89	50	Biased	24.074	24.068	-0.006
90	50	Biased	24.102	24.115	0.013
92	50	Biased	24.191	24.17	-0.021
93	50	Unbiased	24.108	24.11	0.002
94	50	Unbiased	24.107	24.118	0.011
95	50	Unbiased	24.106	24.108	0.002
96	100	Biased	24.135	24.104	-0.031
97	100	Biased	24.2	24.181	-0.019
98	100	Biased	24.169	24.169	0
99	100	Unbiased	24.078	24.097	0.019
100	100	Unbiased	24.065	24.085	0.02
101	100	Unbiased	24.144	24.113	-0.031
102	0	Correlation	24.098	24.095	-0.003
103	0	Correlation	24.073	24.07	-0.003

Test Statistics (µA)

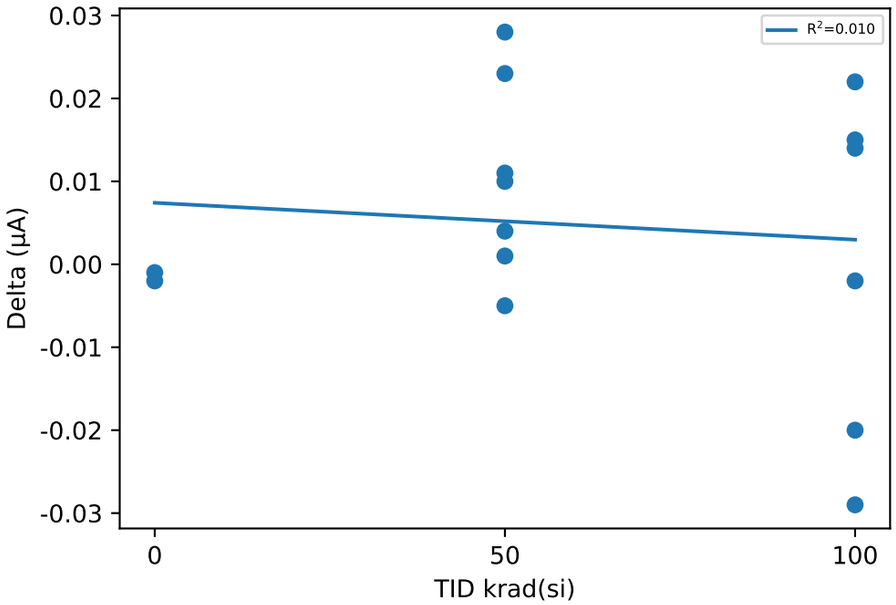
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.073	24.085	24.098	0.017678	24.07	24.082	24.095	0.017678	-0.003	-0.003	-0.003	0
50	24.071	24.108	24.191	0.039694	24.068	24.111	24.17	0.031213	-0.021	0.0028571	0.019	0.013409
100	24.065	24.132	24.2	0.052059	24.085	24.125	24.181	0.040102	-0.031	-0.007	0.02	0.023452

Device Test: 6.31 IHYS(IHYS_SENSE3/SENSE3//14/0/0/0/@IHYS)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 23.28, Upper Limit = 24.72 (µA))

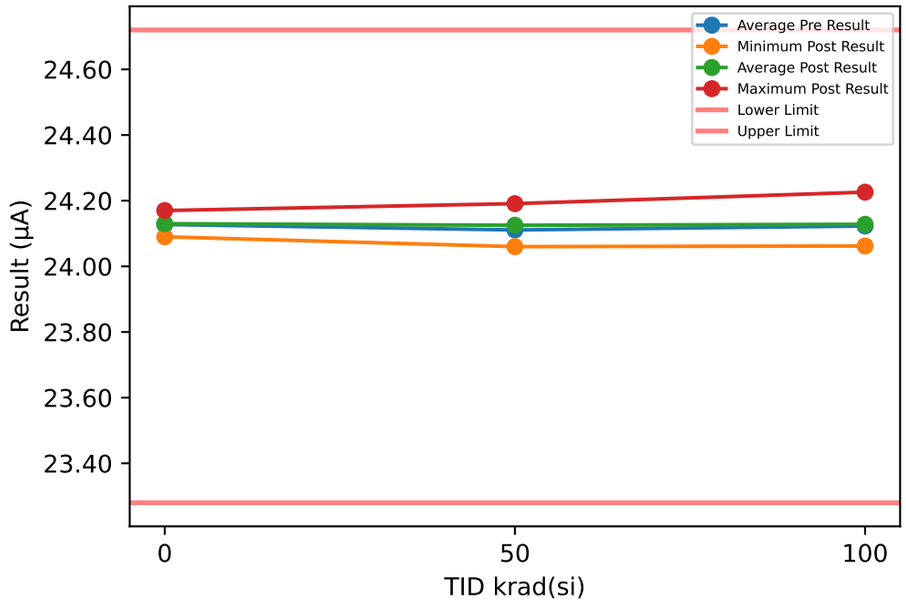
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	24.097	24.125	0.028
89	50	Biased	24.1	24.104	0.004
90	50	Biased	24.151	24.174	0.023
92	50	Biased	24.183	24.178	-0.005
93	50	Unbiased	24.141	24.152	0.011
94	50	Unbiased	24.1	24.11	0.01
95	50	Unbiased	24.2	24.201	0.001
96	100	Biased	24.157	24.137	-0.02
97	100	Biased	24.101	24.099	-0.002
98	100	Biased	24.136	24.151	0.015
99	100	Unbiased	24.16	24.182	0.022
100	100	Unbiased	24.107	24.121	0.014
101	100	Unbiased	24.139	24.11	-0.029
102	0	Correlation	24.206	24.204	-0.002
103	0	Correlation	24.155	24.154	-0.001

Test Statistics (µA)

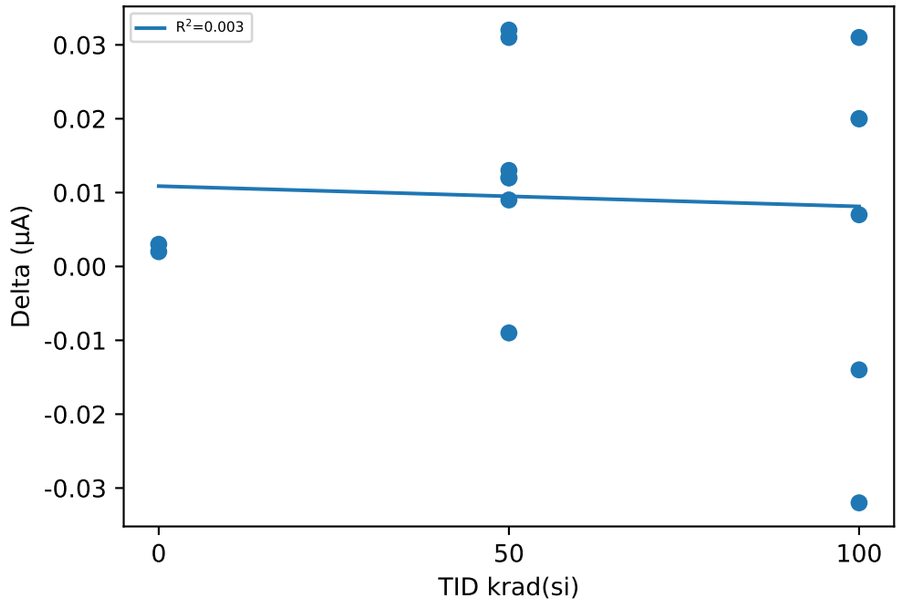
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.155	24.181	24.206	0.036062	24.154	24.179	24.204	0.035355	-0.002	-0.0015	-0.001	0.00070711
50	24.097	24.139	24.2	0.042053	24.104	24.149	24.201	0.037195	-0.005	0.010286	0.028	0.0118
100	24.101	24.133	24.16	0.024695	24.099	24.133	24.182	0.03023	-0.029	0	0.022	0.020736

Device Test: 6.32 IHYS(IHYS_SENSE4/SENSE4//14/0/0/0/@IHYS)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



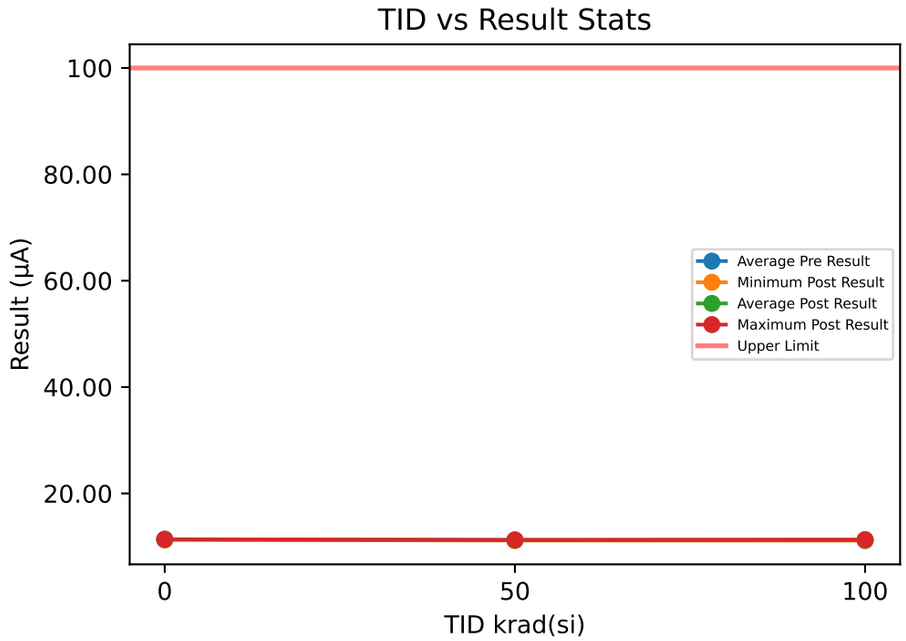
Test Results (Lower Limit = 23.28, Upper Limit = 24.72 (µA))

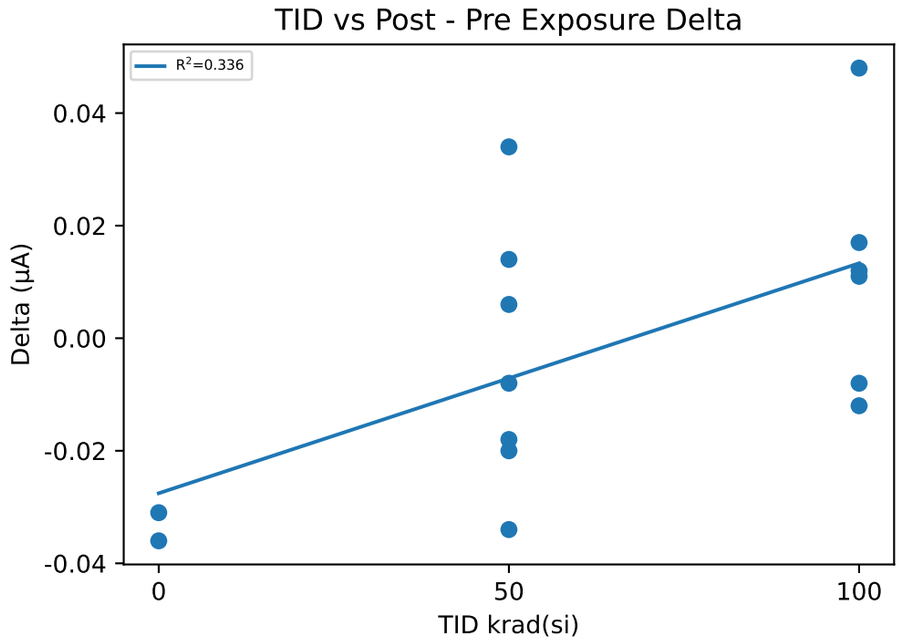
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	24.058	24.089	0.031
89	50	Biased	24.048	24.06	0.012
90	50	Biased	24.159	24.191	0.032
92	50	Biased	24.18	24.171	-0.009
93	50	Unbiased	24.107	24.119	0.012
94	50	Unbiased	24.134	24.147	0.013
95	50	Unbiased	24.09	24.099	0.009
96	100	Biased	24.173	24.159	-0.014
97	100	Biased	24.111	24.118	0.007
98	100	Biased	24.206	24.226	0.02
99	100	Unbiased	24.074	24.105	0.031
100	100	Unbiased	24.079	24.099	0.02
101	100	Unbiased	24.094	24.062	-0.032
102	0	Correlation	24.088	24.09	0.002
103	0	Correlation	24.167	24.17	0.003

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.088	24.128	24.167	0.055861	24.09	24.13	24.17	0.056569	0.002	0.0025	0.003	0.00070711
50	24.048	24.111	24.18	0.049714	24.06	24.125	24.191	0.046884	-0.009	0.014286	0.032	0.013997
100	24.074	24.123	24.206	0.054242	24.062	24.128	24.226	0.057255	-0.032	0.0053333	0.031	0.023914

Device Test: 6.33 PULL_UP_LKG(LEAK_PU1/PULLUP1/3/////@PULL_UP_LKG)





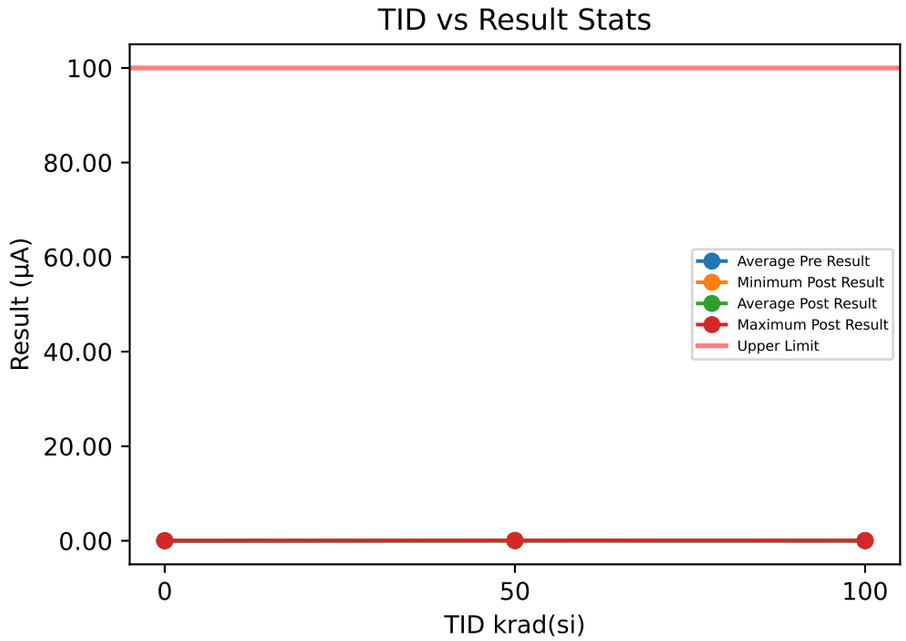
Test Results (Upper Limit = 100.0 (µA))

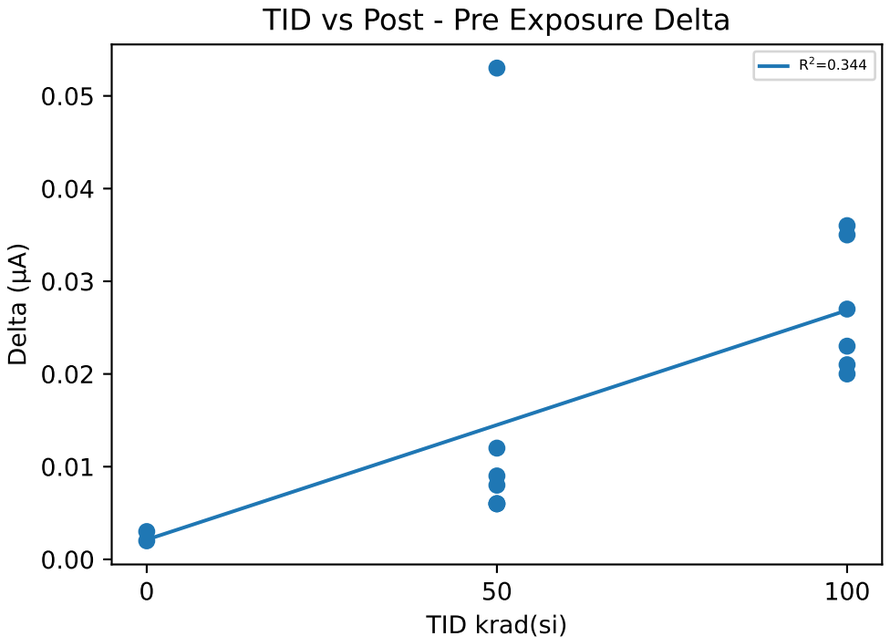
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	11.207	11.187	-0.02
89	50	Biased	11.143	11.157	0.014
90	50	Biased	11.272	11.264	-0.008
92	50	Biased	11.185	11.219	0.034
93	50	Unbiased	11.307	11.273	-0.034
94	50	Unbiased	11.135	11.141	0.006
95	50	Unbiased	11.273	11.255	-0.018
96	100	Biased	11.096	11.113	0.017
97	100	Biased	11.243	11.254	0.011
98	100	Biased	11.274	11.322	0.048
99	100	Unbiased	11.159	11.151	-0.008
100	100	Unbiased	11.232	11.22	-0.012
101	100	Unbiased	11.29	11.302	0.012
102	0	Correlation	11.304	11.268	-0.036
103	0	Correlation	11.421	11.39	-0.031

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.304	11.363	11.421	0.082731	11.268	11.329	11.39	0.086267	-0.036	-0.0335	-0.031	0.0035355
50	11.135	11.217	11.307	0.067803	11.141	11.214	11.273	0.053219	-0.034	-0.0037143	0.034	0.023222
100	11.096	11.216	11.29	0.074126	11.113	11.227	11.322	0.082704	-0.012	0.011333	0.048	0.021426

Device Test: 6.34 PULL_UP_LKG(LEAK_PU2/PULLUP2/3/////@PULL_UP_LKG)





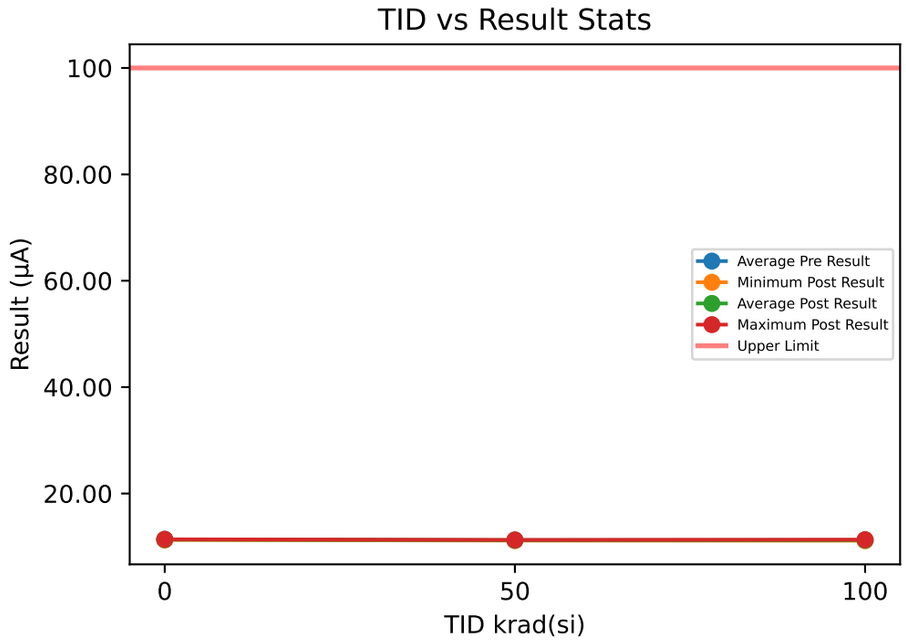
Test Results (Upper Limit = 100.0 (µA))

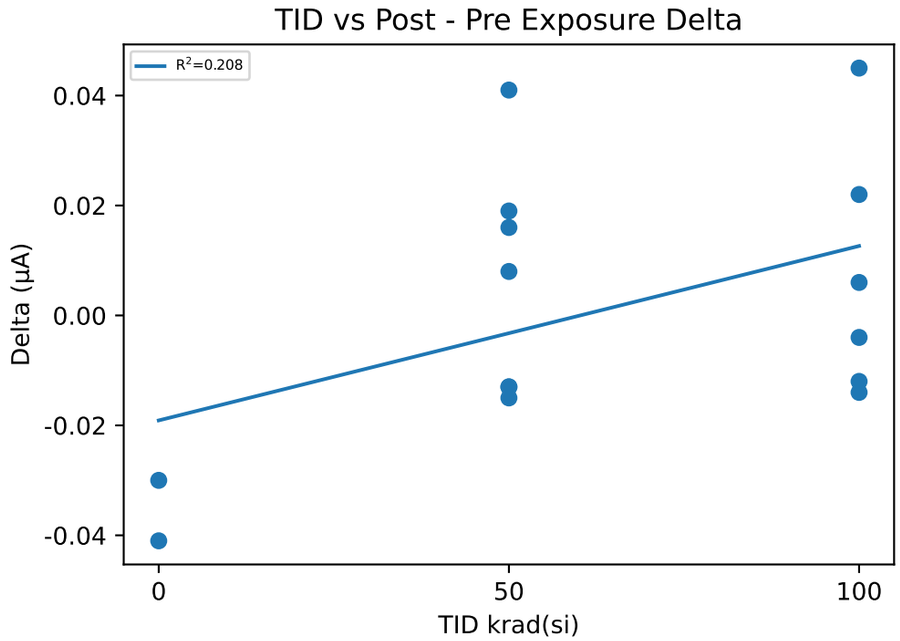
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.01	0.018	0.008
89	50	Biased	0.012	0.021	0.009
90	50	Biased	0.011	0.017	0.006
92	50	Biased	0.014	0.026	0.012
93	50	Unbiased	0.011	0.017	0.006
94	50	Unbiased	0.024	0.077	0.053
95	50	Unbiased	0.011	0.017	0.006
96	100	Biased	0.012	0.039	0.027
97	100	Biased	0.01	0.045	0.035
98	100	Biased	0.011	0.047	0.036
99	100	Unbiased	0.009	0.029	0.02
100	100	Unbiased	0.011	0.032	0.021
101	100	Unbiased	0.012	0.035	0.023
102	0	Correlation	0.01	0.013	0.003
103	0	Correlation	0.012	0.014	0.002

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.01	0.011	0.012	0.0014142	0.013	0.0135	0.014	0.00070711	0.002	0.0025	0.003	0.00070711
50	0.01	0.013286	0.024	0.0048892	0.017	0.027571	0.077	0.022044	0.006	0.014286	0.053	0.017212
100	0.009	0.010833	0.012	0.001169	0.029	0.037833	0.047	0.0071671	0.02	0.027	0.036	0.0070143

Device Test: 6.35 PULL_UP_LKG(LEAK_PU1/PULLUP1/14/////@PULL_UP_LKG)





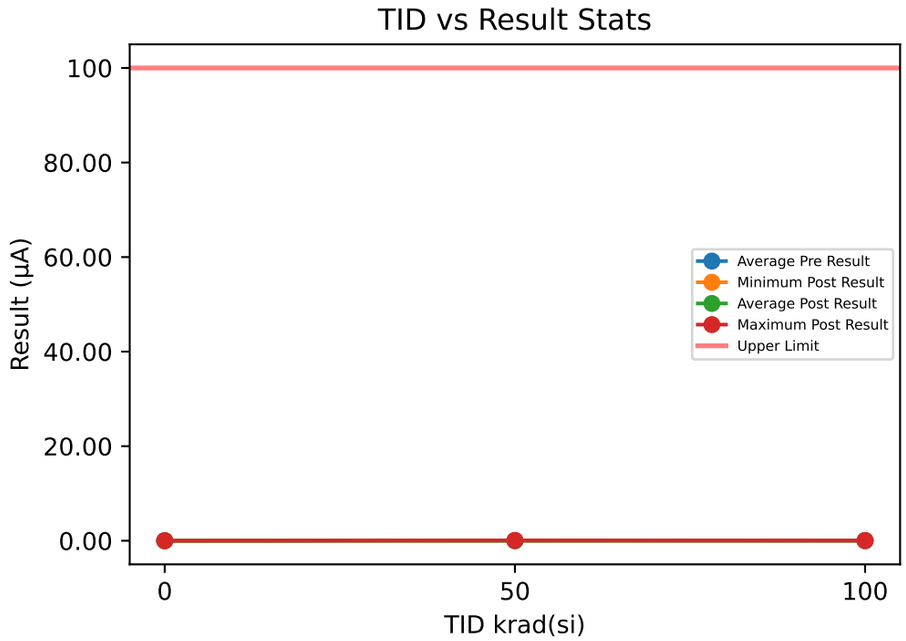
Test Results (Upper Limit = 100.0 (µA))

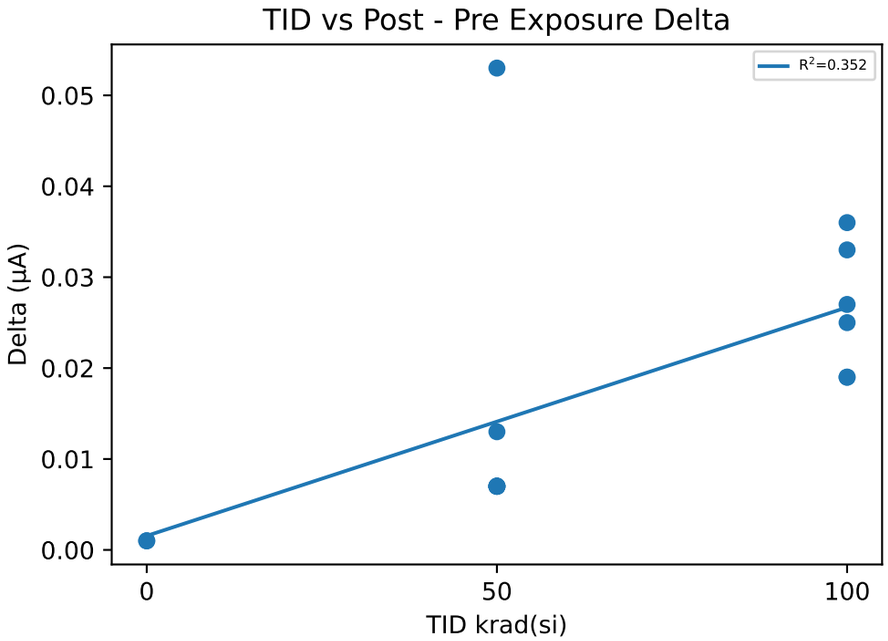
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	11.202	11.187	-0.015
89	50	Biased	11.149	11.157	0.008
90	50	Biased	11.259	11.278	0.019
92	50	Biased	11.197	11.238	0.041
93	50	Unbiased	11.291	11.278	-0.013
94	50	Unbiased	11.136	11.152	0.016
95	50	Unbiased	11.285	11.272	-0.013
96	100	Biased	11.106	11.128	0.022
97	100	Biased	11.255	11.251	-0.004
98	100	Biased	11.282	11.327	0.045
99	100	Unbiased	11.173	11.161	-0.012
100	100	Unbiased	11.238	11.224	-0.014
101	100	Unbiased	11.298	11.304	0.006
102	0	Correlation	11.316	11.275	-0.041
103	0	Correlation	11.425	11.395	-0.03

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.316	11.37	11.425	0.077075	11.275	11.335	11.395	0.084853	-0.041	-0.0355	-0.03	0.0077782
50	11.136	11.217	11.291	0.062815	11.152	11.223	11.278	0.056817	-0.015	0.0061429	0.041	0.021059
100	11.106	11.225	11.298	0.072817	11.128	11.232	11.327	0.078089	-0.014	0.0071667	0.045	0.022772

Device Test: 6.36 PULL_UP_LKG(LEAK_PU2/PULLUP2/14/////@PULL_UP_LKG)





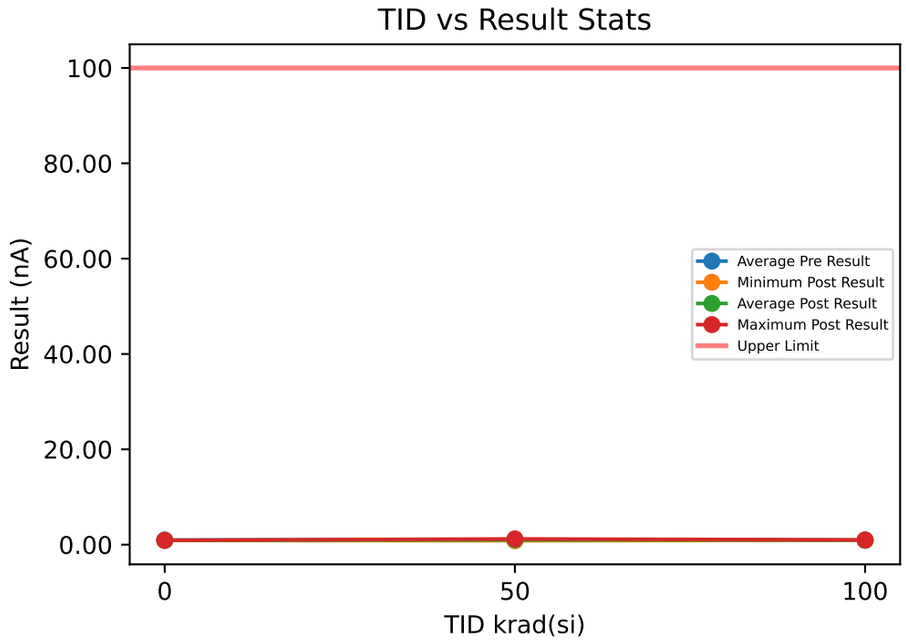
Test Results (Upper Limit = 100.0 (µA))

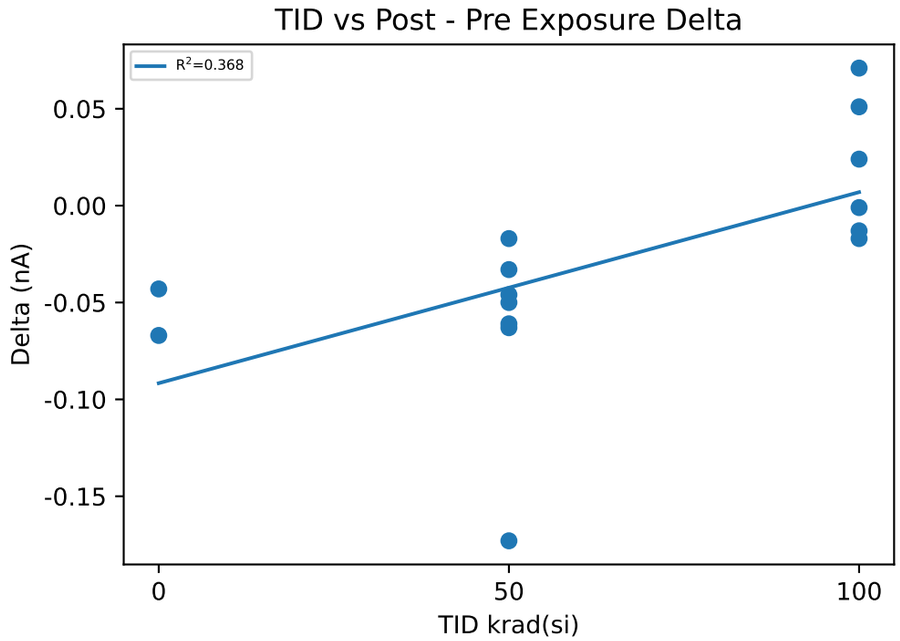
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.004	0.011	0.007
89	50	Biased	0.006	0.013	0.007
90	50	Biased	0.003	0.01	0.007
92	50	Biased	0.006	0.019	0.013
93	50	Unbiased	0.004	0.011	0.007
94	50	Unbiased	0.017	0.07	0.053
95	50	Unbiased	0.004	0.011	0.007
96	100	Biased	0.004	0.031	0.027
97	100	Biased	0.004	0.037	0.033
98	100	Biased	0.004	0.04	0.036
99	100	Unbiased	0.005	0.024	0.019
100	100	Unbiased	0.005	0.024	0.019
101	100	Unbiased	0.004	0.029	0.025
102	0	Correlation	0.004	0.005	0.001
103	0	Correlation	0.006	0.007	0.001

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.004	0.005	0.006	0.0014142	0.005	0.006	0.007	0.0014142	0.001	0.001	0.001	0
50	0.003	0.0062857	0.017	0.004855	0.01	0.020714	0.07	0.021945	0.007	0.014429	0.053	0.017155
100	0.004	0.0043333	0.005	0.0005164	0.024	0.030833	0.04	0.0066156	0.019	0.0265	0.036	0.0070356

Device Test: 6.37 ILKG_WDI(ILKG_WDI/WDI//3/0/0/0/@ILKG_WDI)





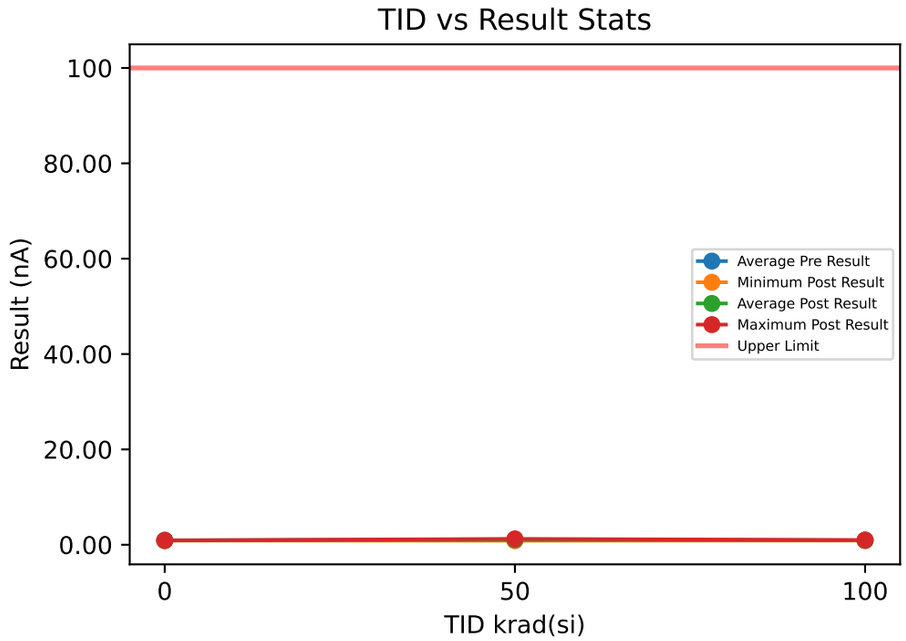
Test Results (Upper Limit = 100.0 (nA))

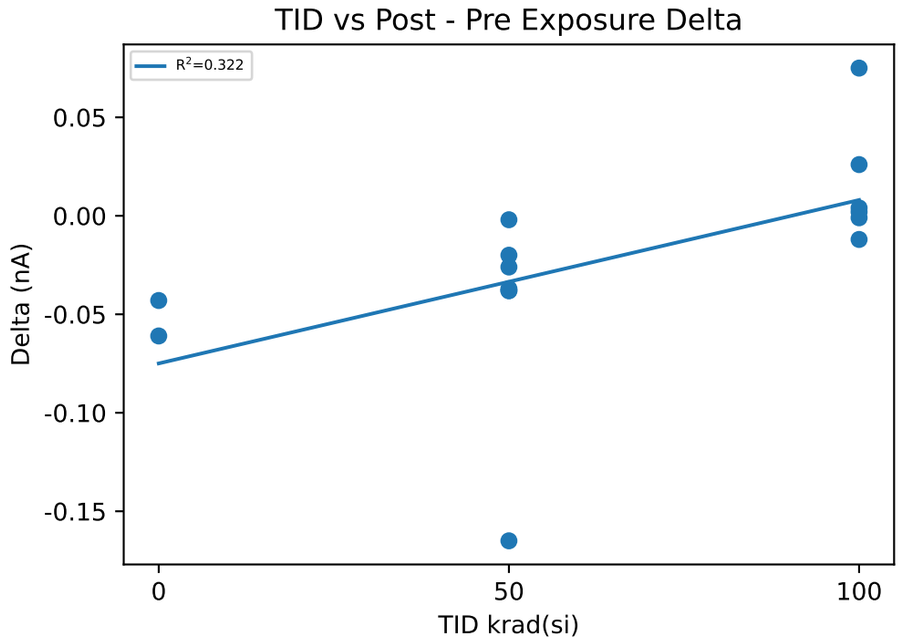
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.24	1.194	-0.046
89	50	Biased	1.265	1.204	-0.061
90	50	Biased	0.899	0.866	-0.033
92	50	Biased	0.89	0.827	-0.063
93	50	Unbiased	1.128	0.955	-0.173
94	50	Unbiased	1.008	0.991	-0.017
95	50	Unbiased	1.065	1.015	-0.05
96	100	Biased	0.899	0.97	0.071
97	100	Biased	0.898	0.922	0.024
98	100	Biased	0.943	0.994	0.051
99	100	Unbiased	0.928	0.927	-0.001
100	100	Unbiased	0.933	0.92	-0.013
101	100	Unbiased	0.95	0.933	-0.017
102	0	Correlation	0.986	0.919	-0.067
103	0	Correlation	0.928	0.885	-0.043

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.928	0.957	0.986	0.041012	0.885	0.902	0.919	0.024042	-0.067	-0.055	-0.043	0.016971
50	0.89	1.0707	1.265	0.15044	0.827	1.0074	1.204	0.14668	-0.173	-0.063286	-0.017	0.050953
100	0.898	0.92517	0.95	0.022031	0.92	0.94433	0.994	0.030481	-0.017	0.019167	0.071	0.03598

Device Test: 6.38 ILKG_WDI(ILKG_WDI/WDI//14/0/0/0/@ILKG_WDI)





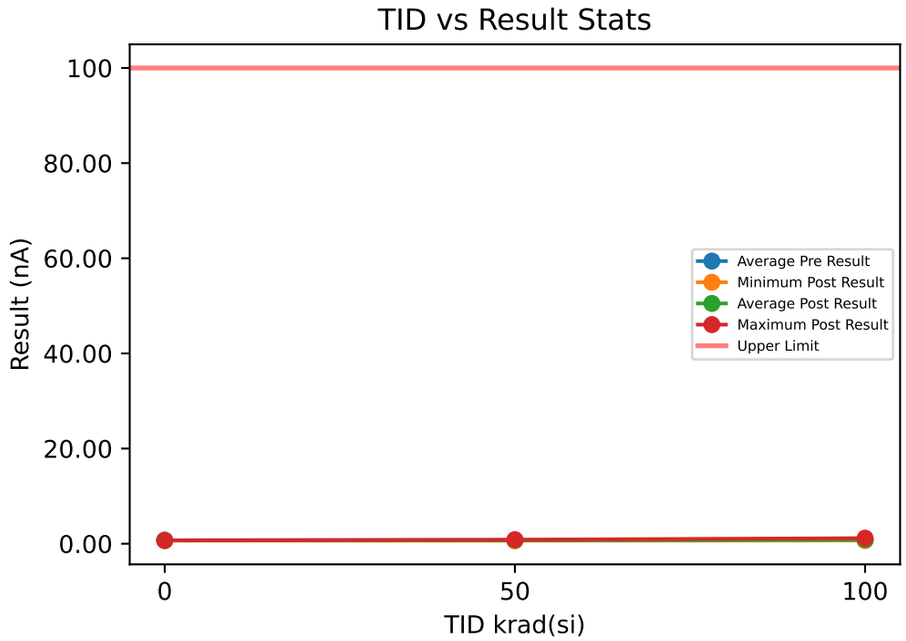
Test Results (Upper Limit = 100.0 (nA))

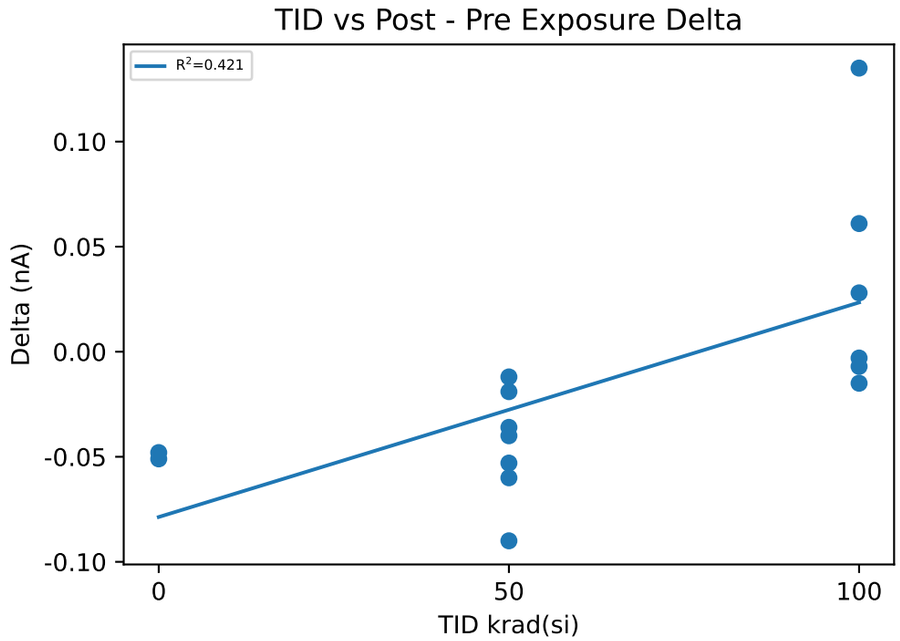
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.232	1.206	-0.026
89	50	Biased	1.251	1.231	-0.02
90	50	Biased	1.042	0.877	-0.165
92	50	Biased	0.885	0.847	-0.038
93	50	Unbiased	0.966	0.964	-0.002
94	50	Unbiased	1.017	0.98	-0.037
95	50	Unbiased	1.051	1.013	-0.038
96	100	Biased	0.901	0.976	0.075
97	100	Biased	0.896	0.898	0.002
98	100	Biased	0.958	0.984	0.026
99	100	Unbiased	0.921	0.925	0.004
100	100	Unbiased	0.898	0.886	-0.012
101	100	Unbiased	0.933	0.932	-0.001
102	0	Correlation	0.966	0.905	-0.061
103	0	Correlation	0.928	0.885	-0.043

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.928	0.947	0.966	0.02687	0.885	0.895	0.905	0.014142	-0.061	-0.052	-0.043	0.012728
50	0.885	1.0634	1.251	0.13398	0.847	1.0169	1.231	0.14956	-0.165	-0.046571	-0.002	0.05382
100	0.896	0.91783	0.958	0.024523	0.886	0.9335	0.984	0.039869	-0.012	0.015667	0.075	0.031602

Device Test: 6.39 ILKG_MODE(ILKG_MODE/MODE//3/0/0/0/@ILKG_MODE)





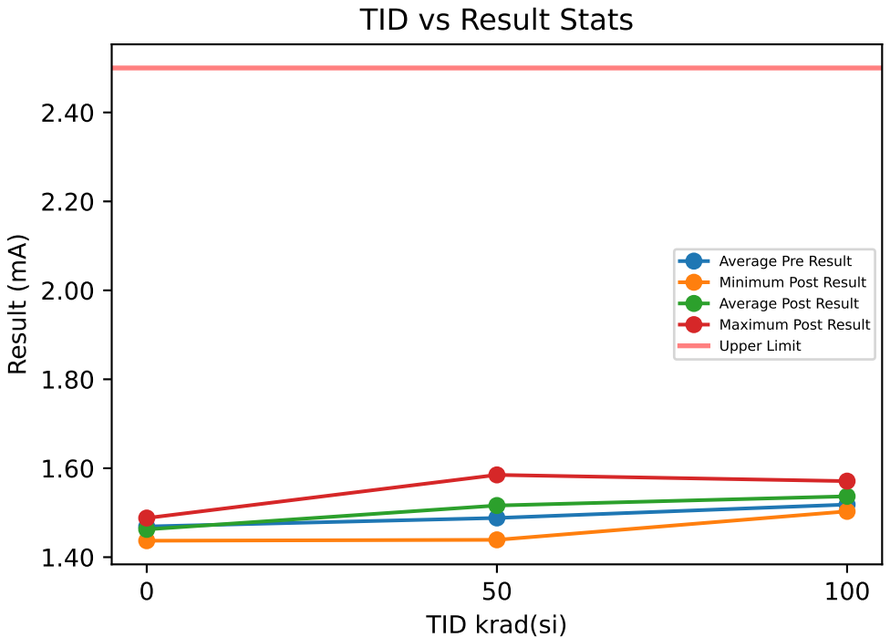
Test Results (Upper Limit = 100.0 (nA))

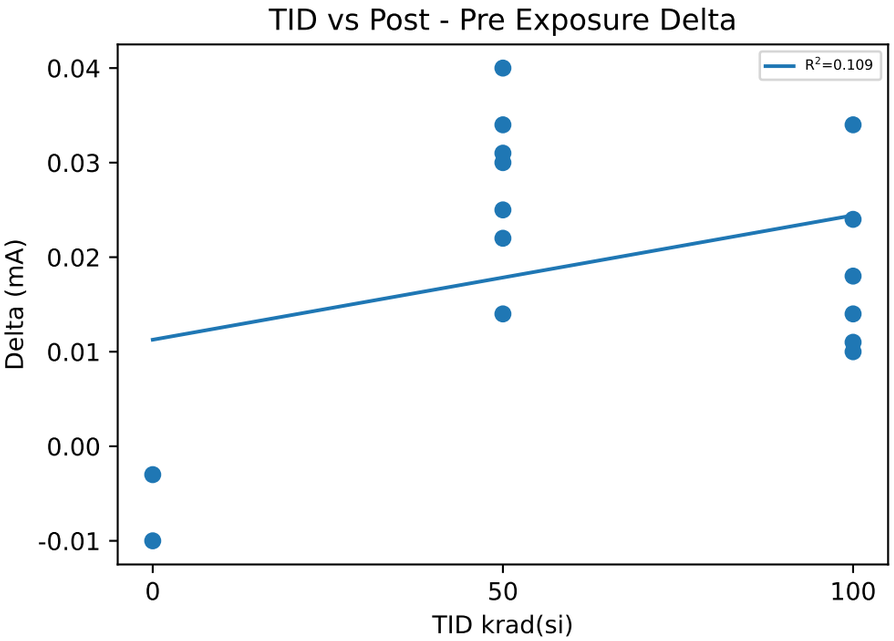
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.73	0.711	-0.019
89	50	Biased	0.714	0.702	-0.012
90	50	Biased	0.675	0.639	-0.036
92	50	Biased	0.883	0.843	-0.04
93	50	Unbiased	0.733	0.673	-0.06
94	50	Unbiased	0.853	0.763	-0.09
95	50	Unbiased	0.681	0.628	-0.053
96	100	Biased	0.697	0.725	0.028
97	100	Biased	0.856	0.917	0.061
98	100	Biased	1.031	1.166	0.135
99	100	Unbiased	0.733	0.718	-0.015
100	100	Unbiased	0.681	0.674	-0.007
101	100	Unbiased	0.702	0.699	-0.003
102	0	Correlation	0.75	0.699	-0.051
103	0	Correlation	0.711	0.663	-0.048

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.711	0.7305	0.75	0.027577	0.663	0.681	0.699	0.025456	-0.051	-0.0495	-0.048	0.0021213
50	0.675	0.75271	0.883	0.082277	0.628	0.70843	0.843	0.074922	-0.09	-0.044286	-0.012	0.026399
100	0.681	0.78333	1.031	0.13689	0.674	0.8165	1.166	0.19206	-0.015	0.033167	0.135	0.057294

Device Test: 6.4 IQ(IQ2_Low/IN//3/0/0/0/@IQ)





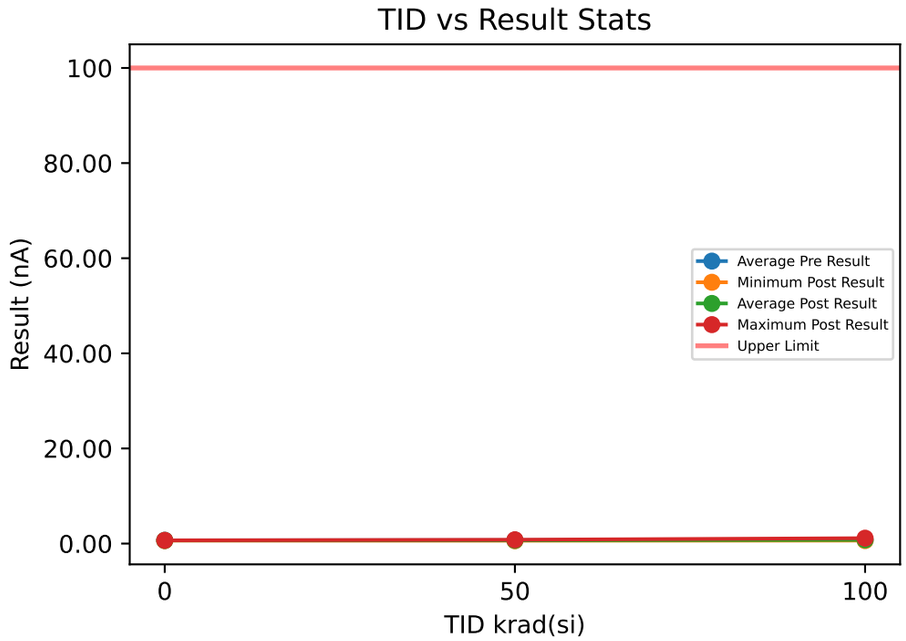
Test Results (Upper Limit = 2.5 (mA))

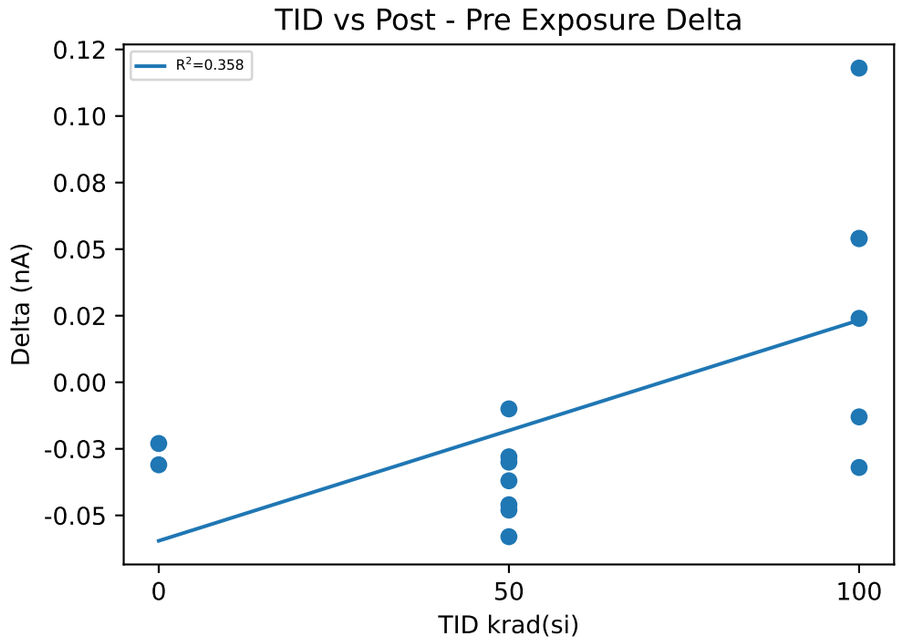
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.478	1.512	0.034
89	50	Biased	1.533	1.564	0.031
90	50	Biased	1.545	1.585	0.04
92	50	Biased	1.501	1.515	0.014
93	50	Unbiased	1.462	1.484	0.022
94	50	Unbiased	1.484	1.514	0.03
95	50	Unbiased	1.414	1.439	0.025
96	100	Biased	1.56	1.571	0.011
97	100	Biased	1.469	1.503	0.034
98	100	Biased	1.52	1.53	0.01
99	100	Unbiased	1.532	1.55	0.018
100	100	Unbiased	1.511	1.525	0.014
101	100	Unbiased	1.518	1.542	0.024
102	0	Correlation	1.491	1.488	-0.003
103	0	Correlation	1.447	1.437	-0.01

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.447	1.469	1.491	0.031113	1.437	1.4625	1.488	0.036062	-0.01	-0.0065	-0.003	0.0049497
50	1.414	1.4881	1.545	0.044179	1.439	1.5161	1.585	0.048372	0.014	0.028	0.04	0.0085049
100	1.469	1.5183	1.56	0.02971	1.503	1.5368	1.571	0.023233	0.01	0.0185	0.034	0.0091597

Device Test: 6.40 ILKG_MODE(ILKG_MODE/MODE//14/0/0/0/@ILKG_MODE)





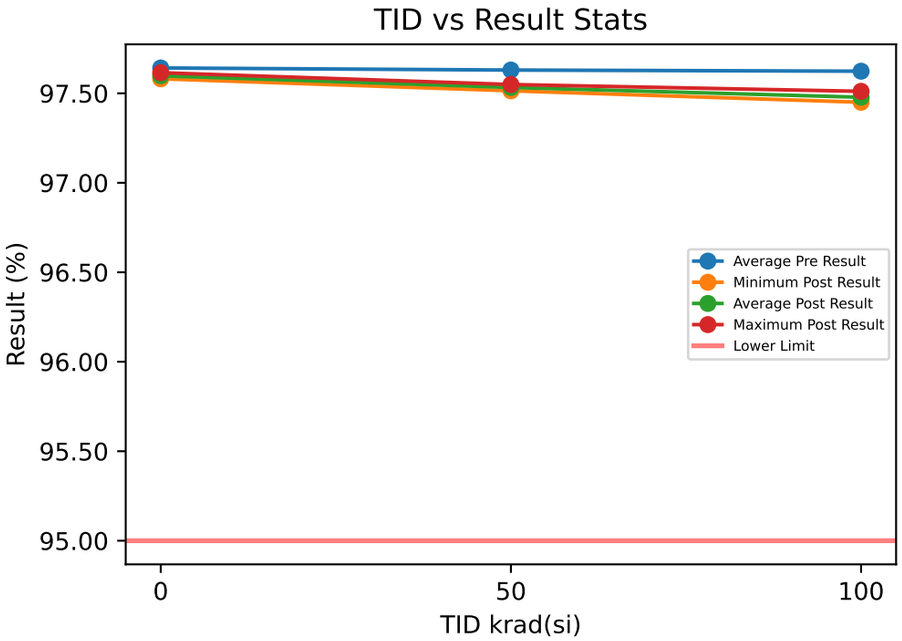
Test Results (Upper Limit = 100.0 (nA))

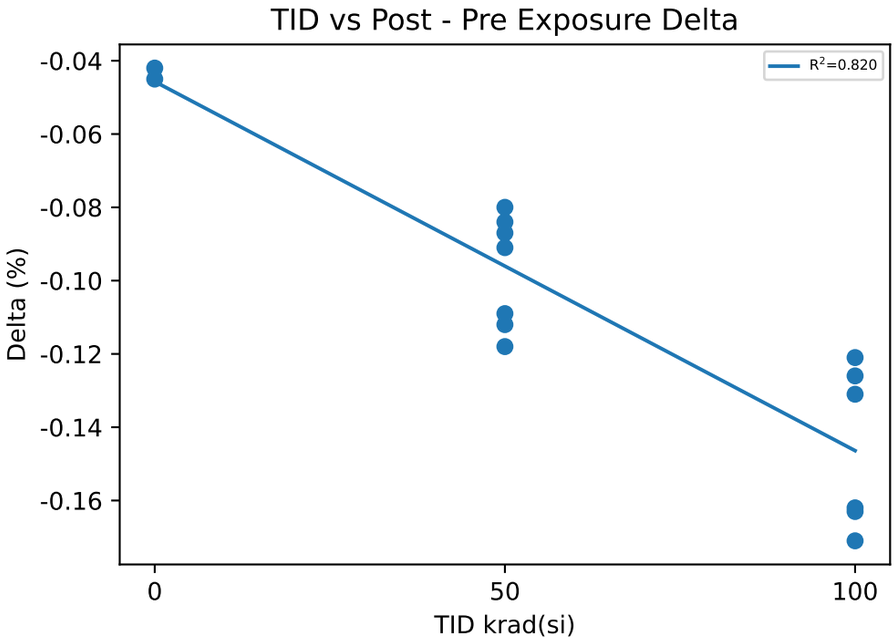
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.685	0.657	-0.028
89	50	Biased	0.673	0.663	-0.01
90	50	Biased	0.64	0.603	-0.037
92	50	Biased	0.854	0.806	-0.048
93	50	Unbiased	0.689	0.643	-0.046
94	50	Unbiased	0.808	0.75	-0.058
95	50	Unbiased	0.631	0.601	-0.03
96	100	Biased	0.637	0.691	0.054
97	100	Biased	0.819	0.873	0.054
98	100	Biased	1.016	1.134	0.118
99	100	Unbiased	0.692	0.679	-0.013
100	100	Unbiased	0.662	0.63	-0.032
101	100	Unbiased	0.643	0.667	0.024
102	0	Correlation	0.703	0.68	-0.023
103	0	Correlation	0.66	0.629	-0.031

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.66	0.6815	0.703	0.030406	0.629	0.6545	0.68	0.036062	-0.031	-0.027	-0.023	0.0056569
50	0.631	0.71143	0.854	0.085539	0.601	0.67471	0.806	0.076308	-0.058	-0.036714	-0.01	0.015819
100	0.637	0.74483	1.016	0.14878	0.63	0.779	1.134	0.19357	-0.032	0.034167	0.118	0.05389

Device Test: 6.41 VOH_RESET_2MA(VOH_2mA_RESETB1/RESETB1/1.6/3/0/0/2/@VOH_RESET_2MA)





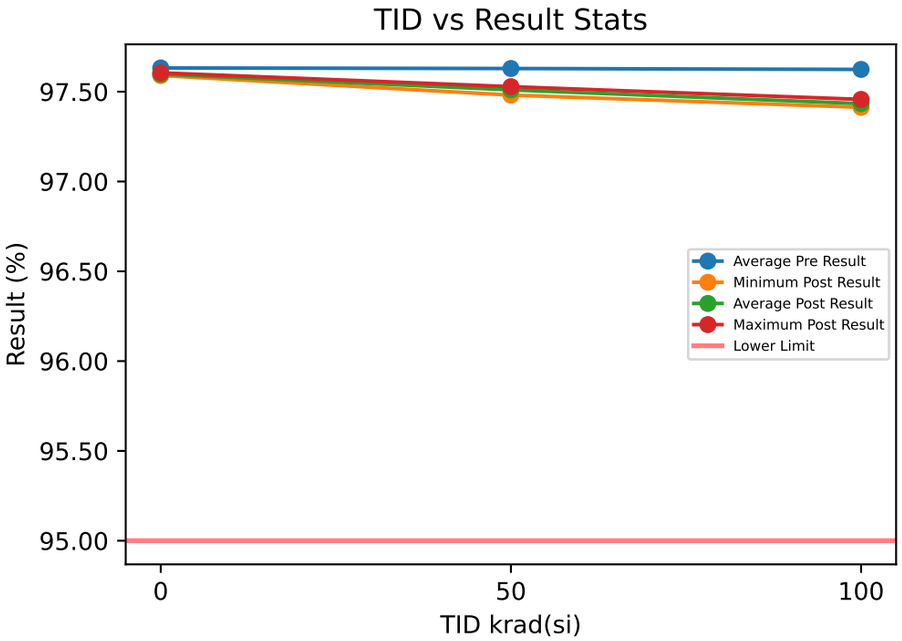
Test Results (Lower Limit = 95.0 (%))

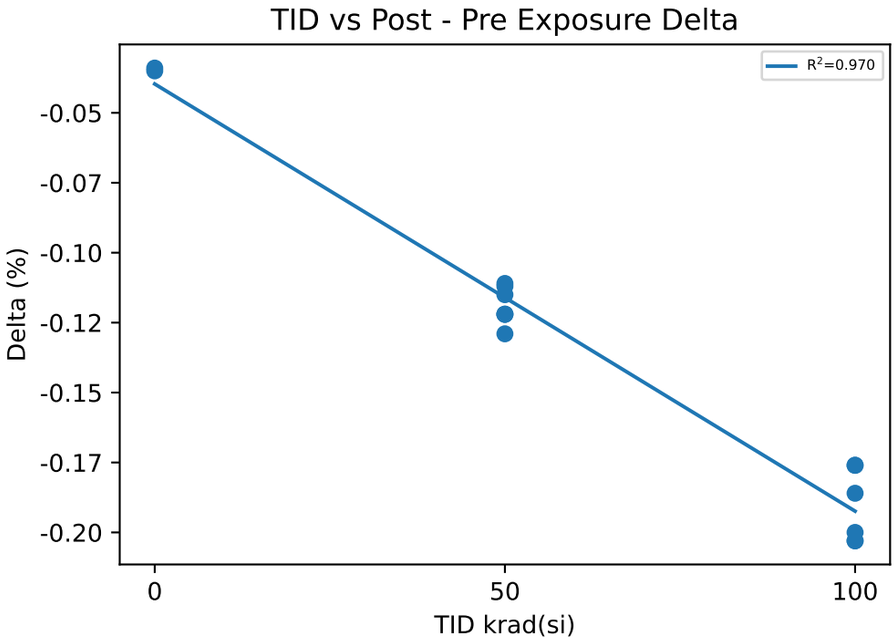
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.618	97.538	-0.08
89	50	Biased	97.634	97.547	-0.087
90	50	Biased	97.633	97.549	-0.084
92	50	Biased	97.606	97.515	-0.091
93	50	Unbiased	97.632	97.514	-0.118
94	50	Unbiased	97.637	97.525	-0.112
95	50	Unbiased	97.649	97.54	-0.109
96	100	Biased	97.623	97.492	-0.131
97	100	Biased	97.625	97.499	-0.126
98	100	Biased	97.632	97.511	-0.121
99	100	Unbiased	97.624	97.461	-0.163
100	100	Unbiased	97.616	97.454	-0.162
101	100	Unbiased	97.621	97.45	-0.171
102	0	Correlation	97.657	97.615	-0.042
103	0	Correlation	97.626	97.581	-0.045

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.626	97.642	97.657	0.02192	97.581	97.598	97.615	0.024042	-0.045	-0.0435	-0.042	0.0021213
50	97.606	97.63	97.649	0.013898	97.514	97.533	97.549	0.01457	-0.118	-0.097286	-0.08	0.015294
100	97.616	97.623	97.632	0.005244	97.45	97.478	97.511	0.02598	-0.171	-0.14567	-0.121	0.021997

Device Test: 6.42 VOH_RESET_2MA(VOH_2mA_RESETB2/RESETB2/1.6/3/0/0/2/@VOH_RESET_2MA)





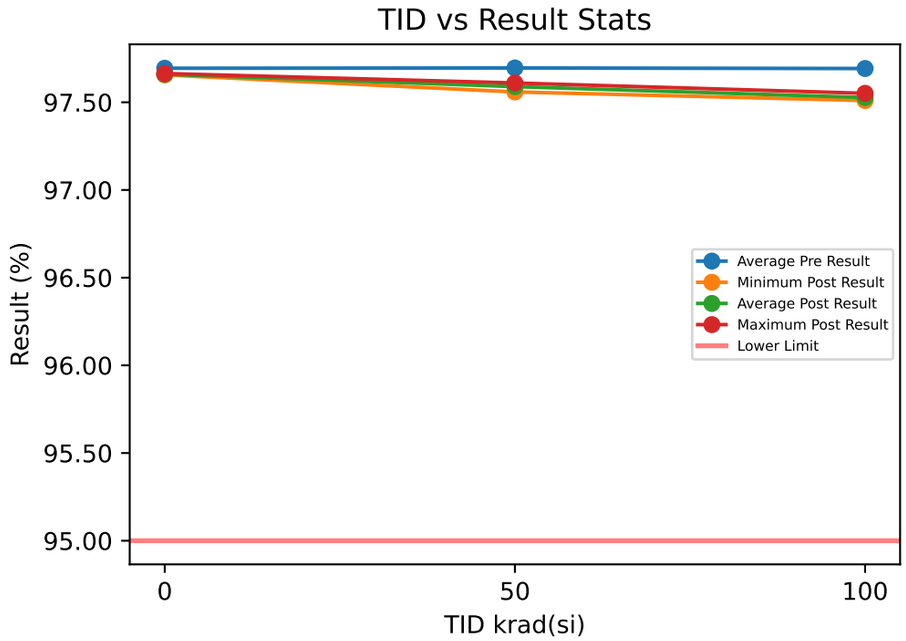
Test Results (Lower Limit = 95.0 (%))

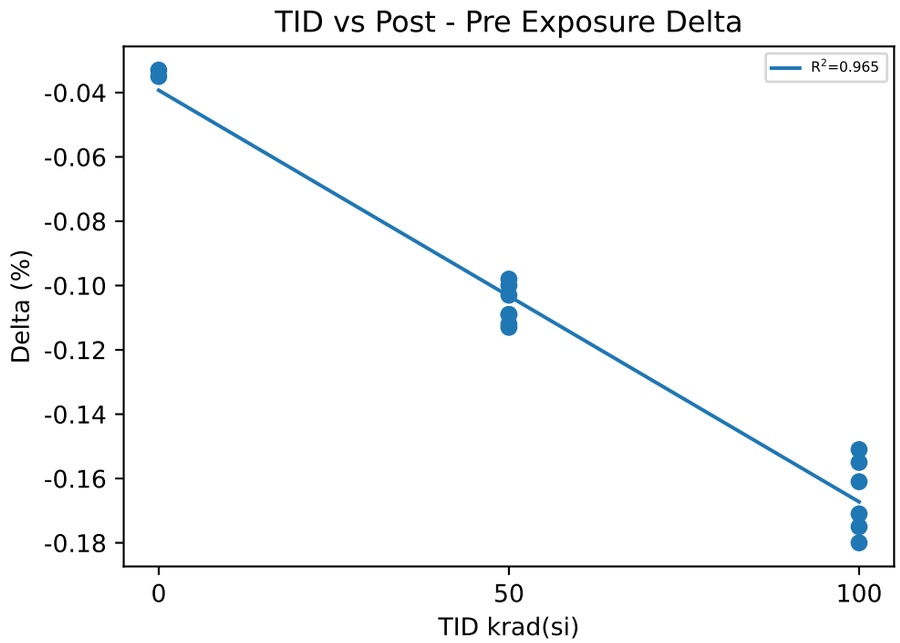
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.636	97.524	-0.112
89	50	Biased	97.645	97.523	-0.122
90	50	Biased	97.625	97.503	-0.122
92	50	Biased	97.61	97.481	-0.129
93	50	Unbiased	97.617	97.495	-0.122
94	50	Unbiased	97.643	97.528	-0.115
95	50	Unbiased	97.627	97.516	-0.111
96	100	Biased	97.627	97.424	-0.203
97	100	Biased	97.616	97.413	-0.203
98	100	Biased	97.629	97.429	-0.2
99	100	Unbiased	97.633	97.457	-0.176
100	100	Unbiased	97.614	97.438	-0.176
101	100	Unbiased	97.625	97.439	-0.186
102	0	Correlation	97.639	97.605	-0.034
103	0	Correlation	97.625	97.59	-0.035

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.625	97.632	97.639	0.0098995	97.59	97.597	97.605	0.010607	-0.035	-0.0345	-0.034	0.00070711
50	97.61	97.629	97.645	0.013077	97.481	97.51	97.528	0.017512	-0.129	-0.119	-0.111	0.006532
100	97.614	97.624	97.633	0.0074833	97.413	97.433	97.457	0.015055	-0.203	-0.19067	-0.176	0.012987

Device Test: 6.43 VOH_RESET_2MA(VOH_2mA_RESETB3/RESETB3/1.6/3/0/0/2/@VOH_RESET_2MA)





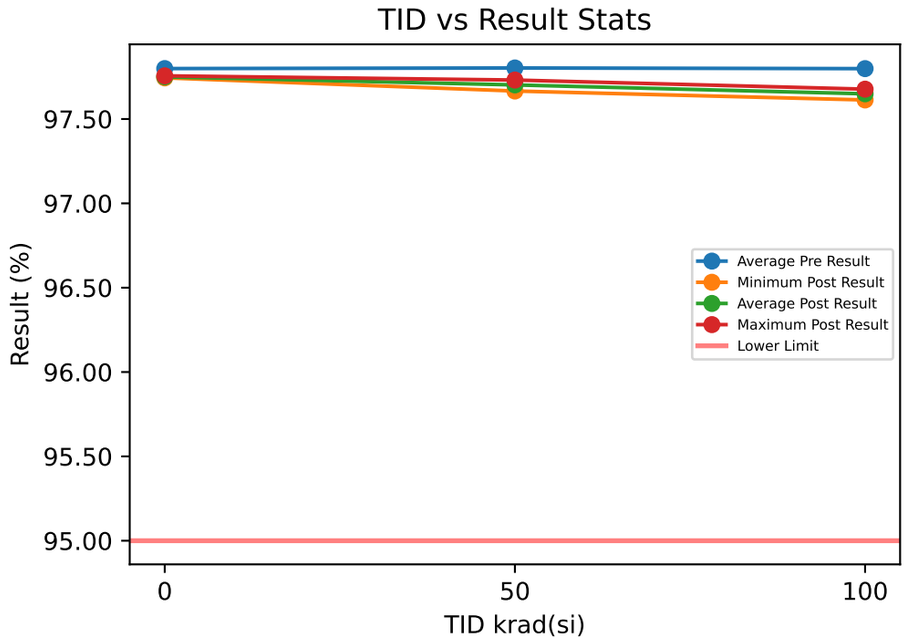
Test Results (Lower Limit = 95.0 (%))

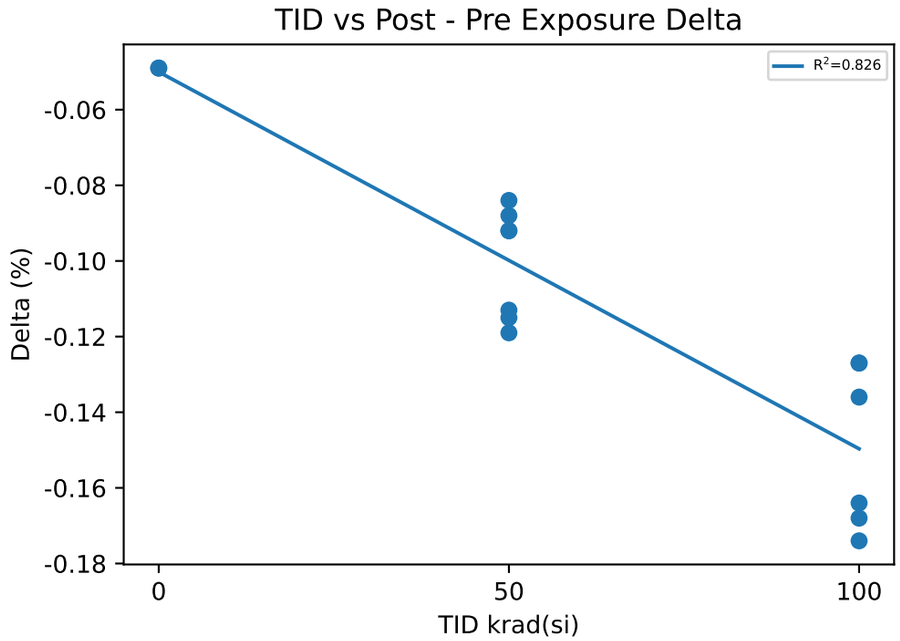
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.698	97.598	-0.1
89	50	Biased	97.718	97.609	-0.109
90	50	Biased	97.7	97.588	-0.112
92	50	Biased	97.672	97.559	-0.113
93	50	Unbiased	97.682	97.573	-0.109
94	50	Unbiased	97.713	97.61	-0.103
95	50	Unbiased	97.686	97.588	-0.098
96	100	Biased	97.7	97.52	-0.18
97	100	Biased	97.685	97.51	-0.175
98	100	Biased	97.702	97.531	-0.171
99	100	Unbiased	97.702	97.551	-0.151
100	100	Unbiased	97.687	97.532	-0.155
101	100	Unbiased	97.679	97.518	-0.161
102	0	Correlation	97.697	97.664	-0.033
103	0	Correlation	97.691	97.656	-0.035

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.691	97.694	97.697	0.0042426	97.656	97.66	97.664	0.0056569	-0.035	-0.034	-0.033	0.0014142
50	97.672	97.696	97.718	0.016652	97.559	97.589	97.61	0.018616	-0.113	-0.10629	-0.098	0.0059362
100	97.679	97.692	97.702	0.010055	97.51	97.527	97.551	0.014394	-0.18	-0.1655	-0.151	0.011589

Device Test: 6.44 VOH_RESET_2MA(VOH_2mA_RESETB4/RESETB4/1.6/3/0/0/2/@VOH_RESET_2MA)





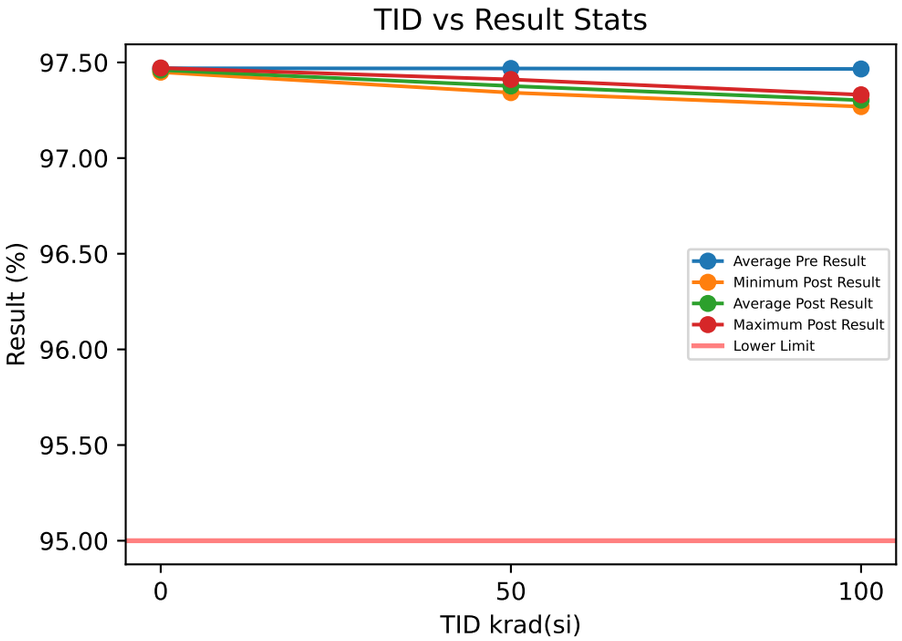
Test Results (Lower Limit = 95.0 (%))

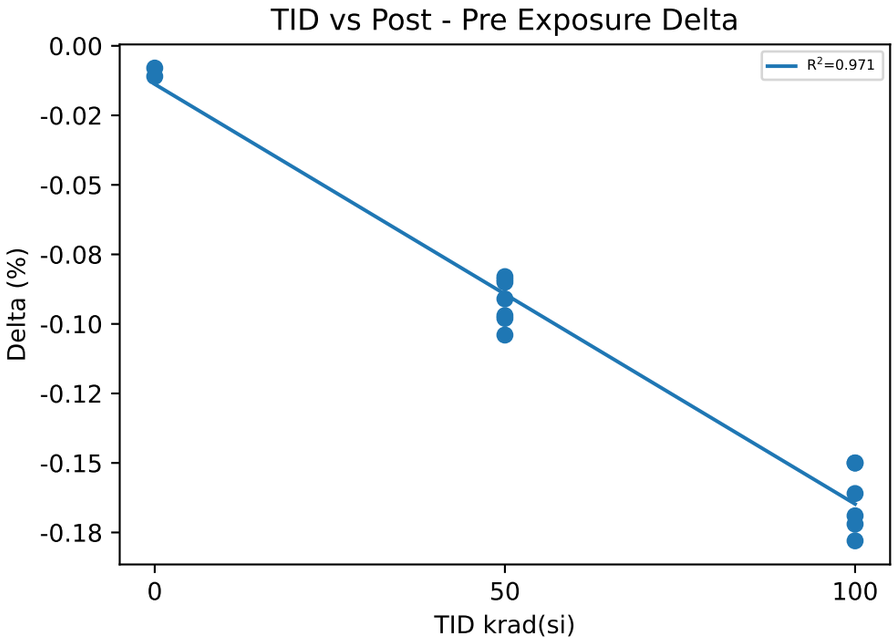
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.808	97.724	-0.084
89	50	Biased	97.823	97.731	-0.092
90	50	Biased	97.808	97.72	-0.088
92	50	Biased	97.779	97.687	-0.092
93	50	Unbiased	97.785	97.666	-0.119
94	50	Unbiased	97.821	97.706	-0.115
95	50	Unbiased	97.794	97.681	-0.113
96	100	Biased	97.813	97.677	-0.136
97	100	Biased	97.791	97.664	-0.127
98	100	Biased	97.801	97.674	-0.127
99	100	Unbiased	97.809	97.645	-0.164
100	100	Unbiased	97.791	97.623	-0.168
101	100	Unbiased	97.787	97.613	-0.174
102	0	Correlation	97.805	97.756	-0.049
103	0	Correlation	97.793	97.744	-0.049

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.793	97.799	97.805	0.0084853	97.744	97.75	97.756	0.0084853	-0.049	-0.049	-0.049	0
50	97.779	97.803	97.823	0.017096	97.666	97.702	97.731	0.024586	-0.119	-0.10043	-0.084	0.014616
100	97.787	97.799	97.813	0.01069	97.613	97.649	97.677	0.026912	-0.174	-0.14933	-0.127	0.021667

Device Test: 6.45 VOH_WDO_2MA(VOH_2mA_WDOB/WDOB/1.6/3/0/0/2/@VOH_WDO_2MA)





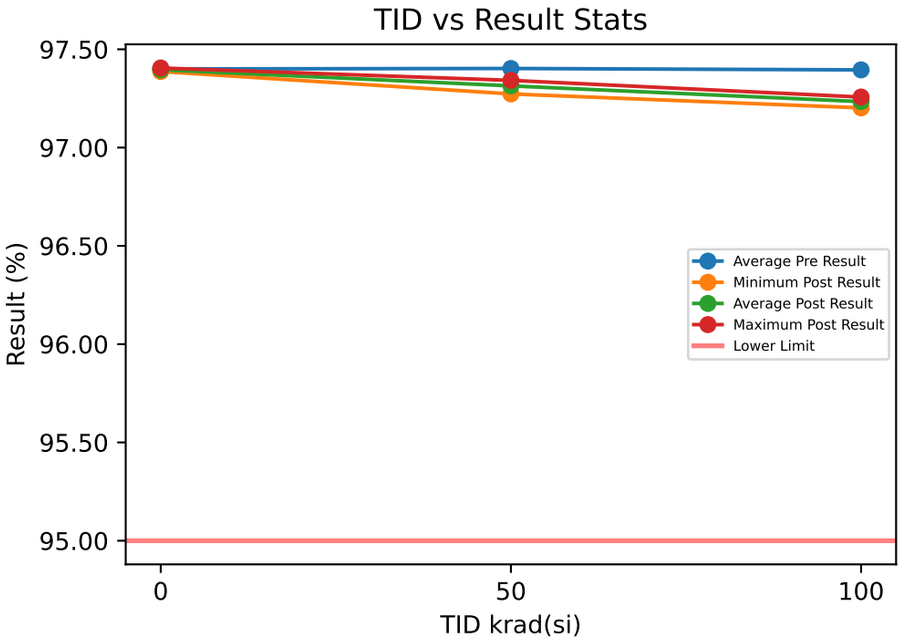
Test Results (Lower Limit = 95.0 (%))

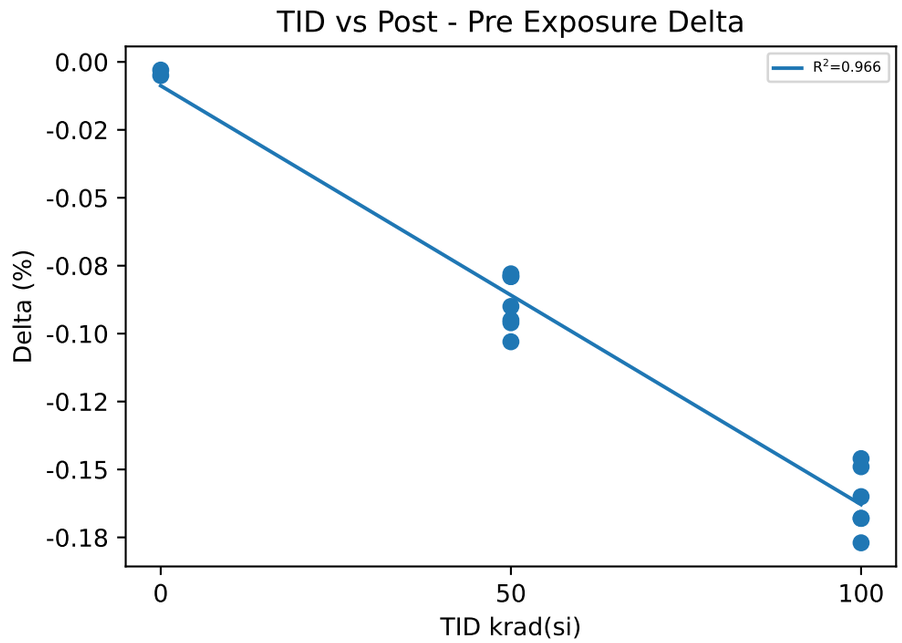
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.478	97.395	-0.083
89	50	Biased	97.493	97.395	-0.098
90	50	Biased	97.476	97.379	-0.097
92	50	Biased	97.446	97.342	-0.104
93	50	Unbiased	97.444	97.353	-0.091
94	50	Unbiased	97.495	97.411	-0.084
95	50	Unbiased	97.447	97.362	-0.085
96	100	Biased	97.486	97.317	-0.169
97	100	Biased	97.447	97.269	-0.178
98	100	Biased	97.465	97.293	-0.172
99	100	Unbiased	97.481	97.331	-0.15
100	100	Unbiased	97.468	97.318	-0.15
101	100	Unbiased	97.448	97.287	-0.161
102	0	Correlation	97.479	97.471	-0.008
103	0	Correlation	97.46	97.449	-0.011

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.46	97.469	97.479	0.013435	97.449	97.46	97.471	0.015556	-0.011	-0.0095	-0.008	0.0021213
50	97.444	97.468	97.495	0.022427	97.342	97.377	97.411	0.025277	-0.104	-0.091714	-0.083	0.0081591
100	97.447	97.466	97.486	0.016216	97.269	97.303	97.331	0.023305	-0.178	-0.16333	-0.15	0.01169

Device Test: 6.46 VOH_PWRGD_2MA(VOH_2mA_PWRGD/PWRGD/1.6/3/0/0/2/@VOH_PWRGD_2MA)





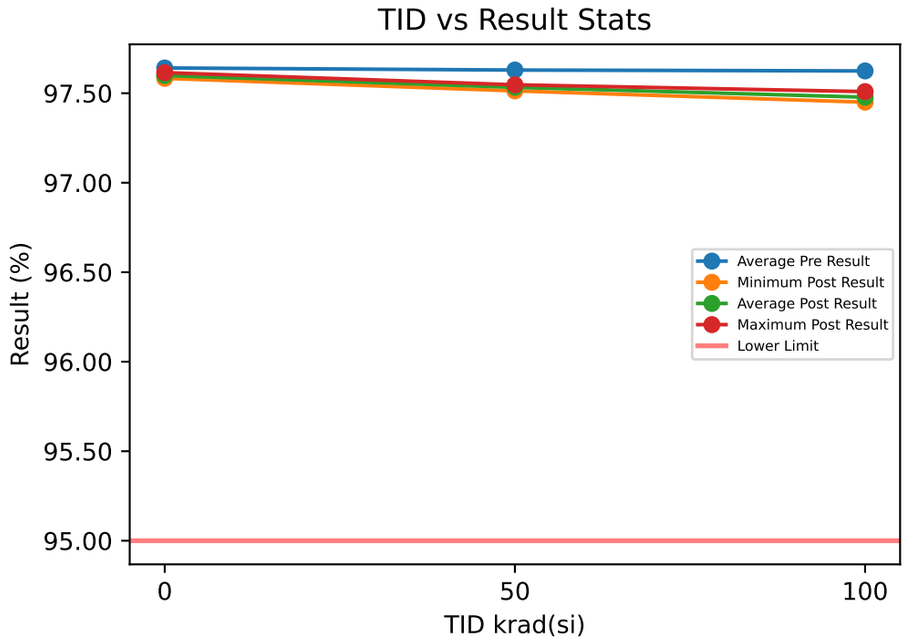
Test Results (Lower Limit = 95.0 (%))

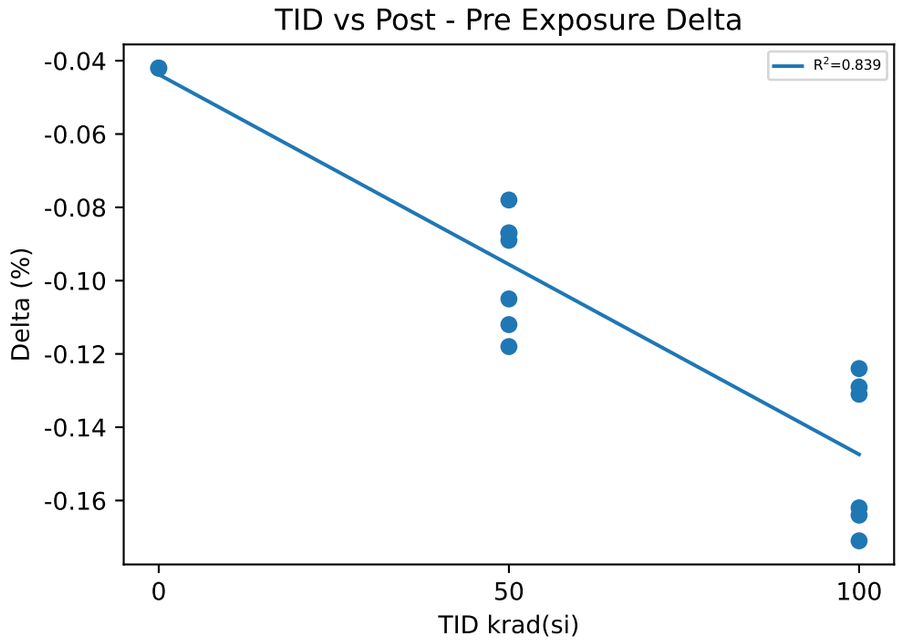
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.42	97.342	-0.078
89	50	Biased	97.425	97.329	-0.096
90	50	Biased	97.406	97.311	-0.095
92	50	Biased	97.376	97.273	-0.103
93	50	Unbiased	97.381	97.291	-0.09
94	50	Unbiased	97.421	97.342	-0.079
95	50	Unbiased	97.388	97.309	-0.079
96	100	Biased	97.406	97.238	-0.168
97	100	Biased	97.379	97.202	-0.177
98	100	Biased	97.4	97.232	-0.168
99	100	Unbiased	97.403	97.257	-0.146
100	100	Unbiased	97.394	97.245	-0.149
101	100	Unbiased	97.39	97.23	-0.16
102	0	Correlation	97.408	97.405	-0.003
103	0	Correlation	97.392	97.387	-0.005

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.392	97.4	97.408	0.011314	97.387	97.396	97.405	0.012728	-0.005	-0.004	-0.003	0.0014142
50	97.376	97.402	97.425	0.020582	97.273	97.314	97.342	0.025939	-0.103	-0.088571	-0.078	0.010014
100	97.379	97.395	97.406	0.009913	97.202	97.234	97.257	0.018493	-0.177	-0.16133	-0.146	0.012028

Device Test: 6.47 VOH_RESET_2MA(VOH_2mA_RESETB1/RESETB1/1.6/14/0/0/2/@VOH_RESET_2MA)





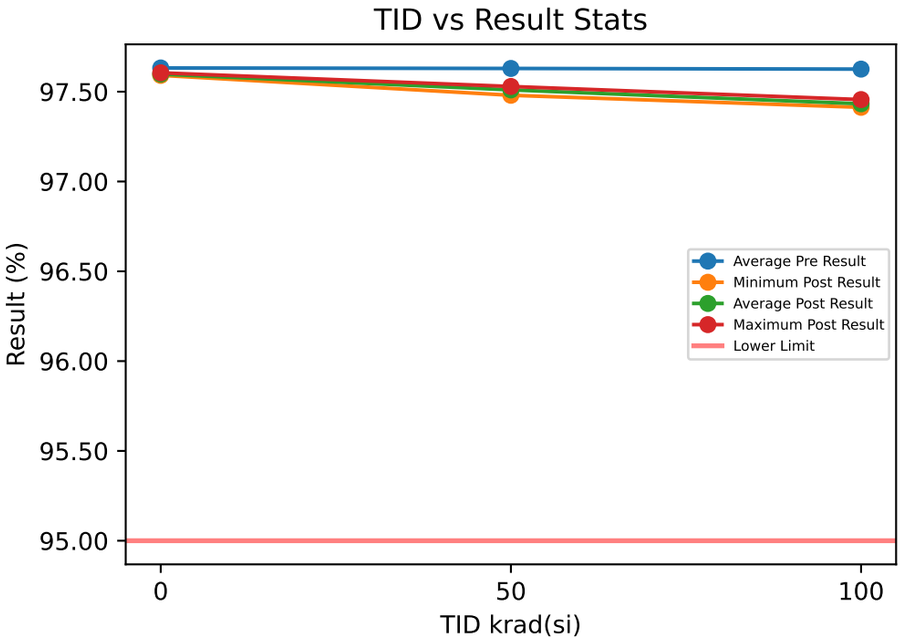
Test Results (Lower Limit = 95.0 (%))

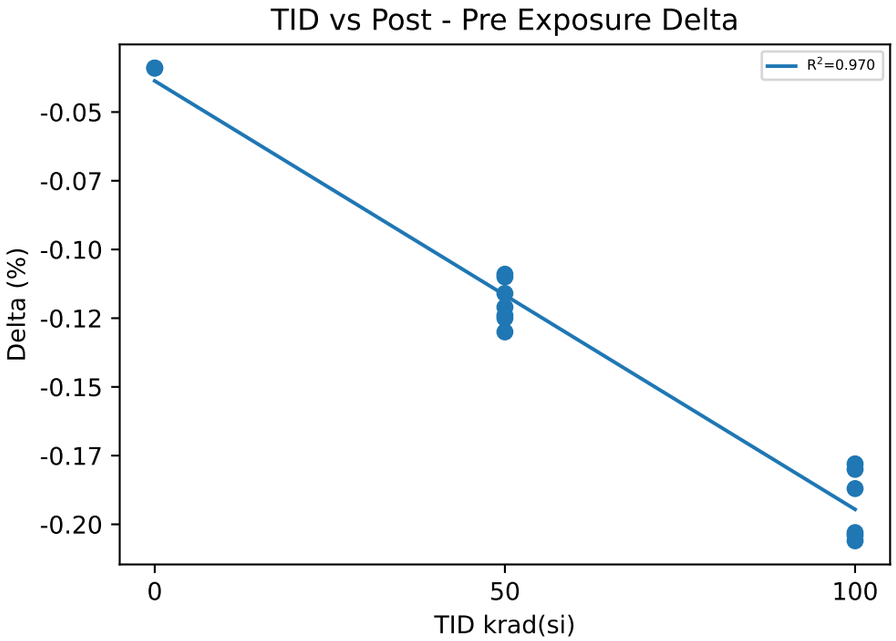
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.618	97.54	-0.078
89	50	Biased	97.634	97.547	-0.087
90	50	Biased	97.633	97.546	-0.087
92	50	Biased	97.605	97.516	-0.089
93	50	Unbiased	97.631	97.513	-0.118
94	50	Unbiased	97.637	97.525	-0.112
95	50	Unbiased	97.648	97.543	-0.105
96	100	Biased	97.624	97.493	-0.131
97	100	Biased	97.628	97.499	-0.129
98	100	Biased	97.633	97.509	-0.124
99	100	Unbiased	97.624	97.462	-0.162
100	100	Unbiased	97.617	97.453	-0.164
101	100	Unbiased	97.621	97.45	-0.171
102	0	Correlation	97.657	97.615	-0.042
103	0	Correlation	97.625	97.583	-0.042

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.625	97.641	97.657	0.022627	97.583	97.599	97.615	0.022627	-0.042	-0.042	-0.042	0
50	97.605	97.629	97.648	0.013939	97.513	97.533	97.547	0.014531	-0.118	-0.096571	-0.078	0.015021
100	97.617	97.624	97.633	0.0055408	97.45	97.478	97.509	0.025657	-0.171	-0.14683	-0.124	0.020971

Device Test: 6.48 VOH_RESET_2MA(VOH_2mA_RESETB2/RESETB2/1.6/14/0/0/2/@VOH_RESET_2MA)





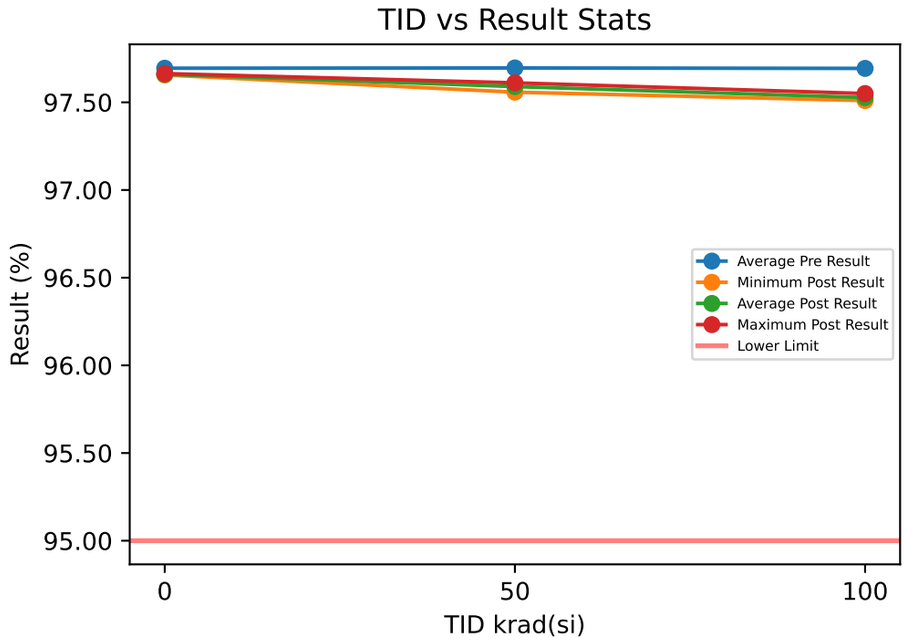
Test Results (Lower Limit = 95.0 (%))

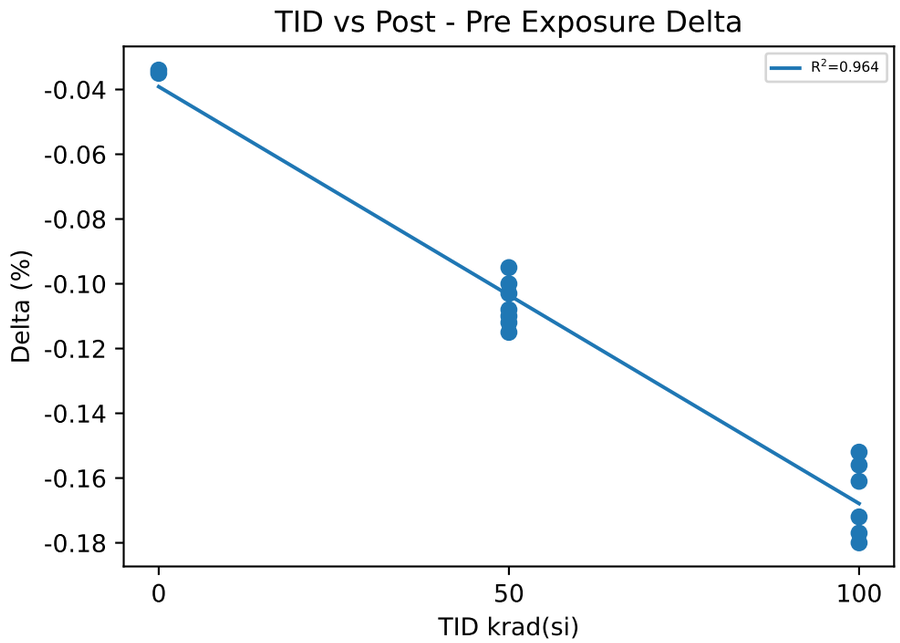
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.635	97.525	-0.11
89	50	Biased	97.646	97.522	-0.124
90	50	Biased	97.626	97.501	-0.125
92	50	Biased	97.61	97.48	-0.13
93	50	Unbiased	97.617	97.496	-0.121
94	50	Unbiased	97.645	97.529	-0.116
95	50	Unbiased	97.626	97.517	-0.109
96	100	Biased	97.628	97.424	-0.204
97	100	Biased	97.619	97.413	-0.206
98	100	Biased	97.632	97.429	-0.203
99	100	Unbiased	97.634	97.456	-0.178
100	100	Unbiased	97.615	97.435	-0.18
101	100	Unbiased	97.626	97.439	-0.187
102	0	Correlation	97.639	97.605	-0.034
103	0	Correlation	97.625	97.591	-0.034

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.625	97.632	97.639	0.0098995	97.591	97.598	97.605	0.0098995	-0.034	-0.034	-0.034	1.0049e-14
50	97.61	97.629	97.646	0.013561	97.48	97.51	97.529	0.018055	-0.13	-0.11929	-0.109	0.0079102
100	97.615	97.626	97.634	0.0073937	97.413	97.433	97.456	0.014597	-0.206	-0.193	-0.178	0.012806

Device Test: 6.49 VOH_RESET_2MA(VOH_2mA_RESETB3/RESETB3/1.6/14/0/0/2/@VOH_RESET_2MA)





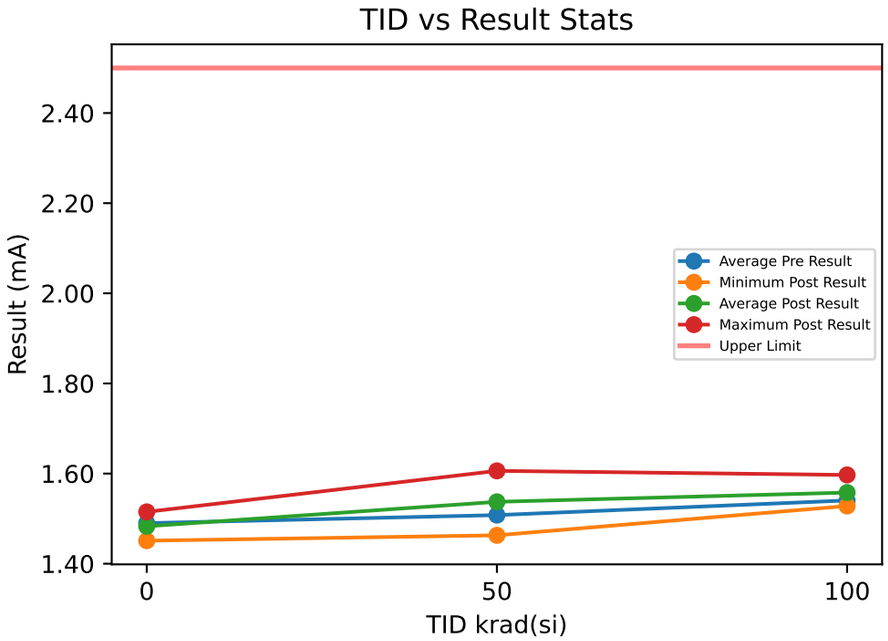
Test Results (Lower Limit = 95.0 (%))

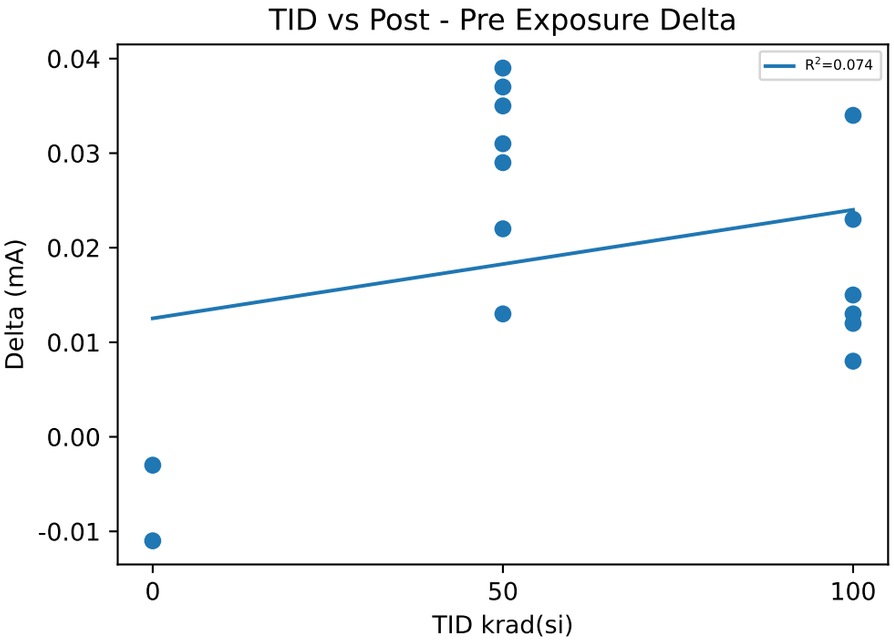
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.698	97.598	-0.1
89	50	Biased	97.719	97.609	-0.11
90	50	Biased	97.698	97.586	-0.112
92	50	Biased	97.673	97.558	-0.115
93	50	Unbiased	97.683	97.575	-0.108
94	50	Unbiased	97.714	97.611	-0.103
95	50	Unbiased	97.686	97.591	-0.095
96	100	Biased	97.701	97.521	-0.18
97	100	Biased	97.687	97.51	-0.177
98	100	Biased	97.704	97.532	-0.172
99	100	Unbiased	97.702	97.55	-0.152
100	100	Unbiased	97.687	97.531	-0.156
101	100	Unbiased	97.68	97.519	-0.161
102	0	Correlation	97.699	97.664	-0.035
103	0	Correlation	97.69	97.656	-0.034

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.69	97.695	97.699	0.006364	97.656	97.66	97.664	0.0056569	-0.035	-0.0345	-0.034	0.00070711
50	97.673	97.696	97.719	0.016628	97.558	97.59	97.611	0.018848	-0.115	-0.10614	-0.095	0.0071047
100	97.68	97.693	97.704	0.010055	97.51	97.527	97.55	0.013848	-0.18	-0.16633	-0.152	0.011605

Device Test: 6.5 IQ(IQ2_Low/IN//14/0/0/0/@IQ)





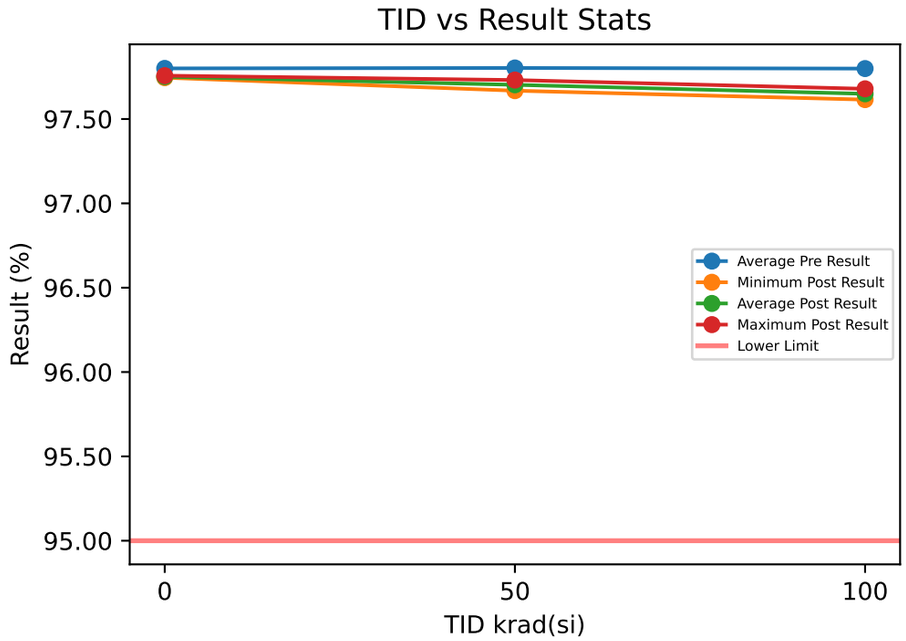
Test Results (Upper Limit = 2.5 (mA))

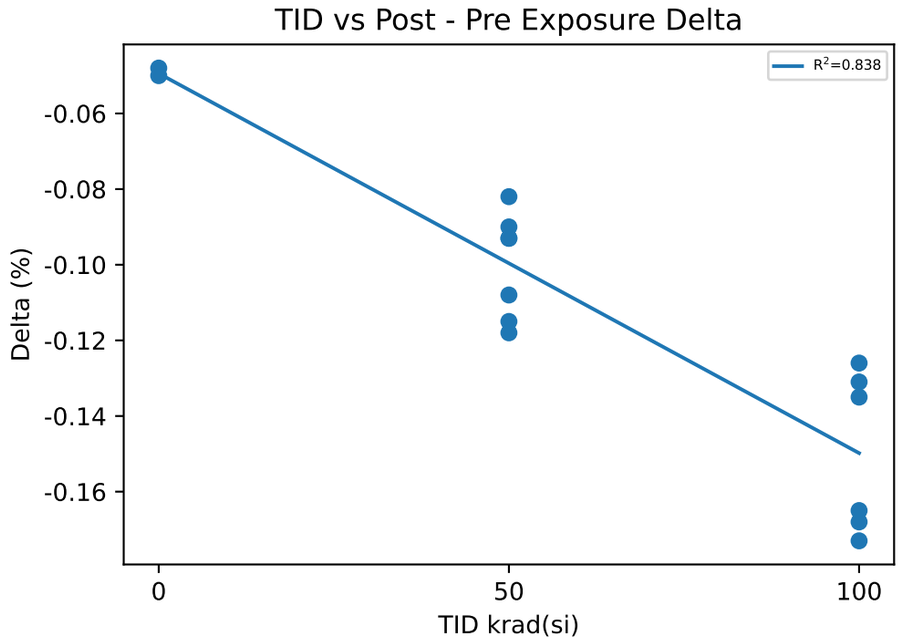
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.494	1.531	0.037
89	50	Biased	1.554	1.585	0.031
90	50	Biased	1.567	1.606	0.039
92	50	Biased	1.522	1.535	0.013
93	50	Unbiased	1.482	1.504	0.022
94	50	Unbiased	1.502	1.537	0.035
95	50	Unbiased	1.434	1.463	0.029
96	100	Biased	1.585	1.597	0.012
97	100	Biased	1.494	1.528	0.034
98	100	Biased	1.547	1.555	0.008
99	100	Unbiased	1.552	1.567	0.015
100	100	Unbiased	1.527	1.54	0.013
101	100	Unbiased	1.537	1.56	0.023
102	0	Correlation	1.518	1.515	-0.003
103	0	Correlation	1.462	1.451	-0.011

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.462	1.49	1.518	0.039598	1.451	1.483	1.515	0.045255	-0.011	-0.007	-0.003	0.0056569
50	1.434	1.5079	1.567	0.04505	1.463	1.5373	1.606	0.047731	0.013	0.029429	0.039	0.0091989
100	1.494	1.5403	1.585	0.030038	1.528	1.5578	1.597	0.023828	0.008	0.0175	0.034	0.0094816

Device Test: 6.50 VOH_RESET_2MA(VOH_2mA_RESETB4/RESETB4/1.6/14/0/0/2/@VOH_RESET_2MA)





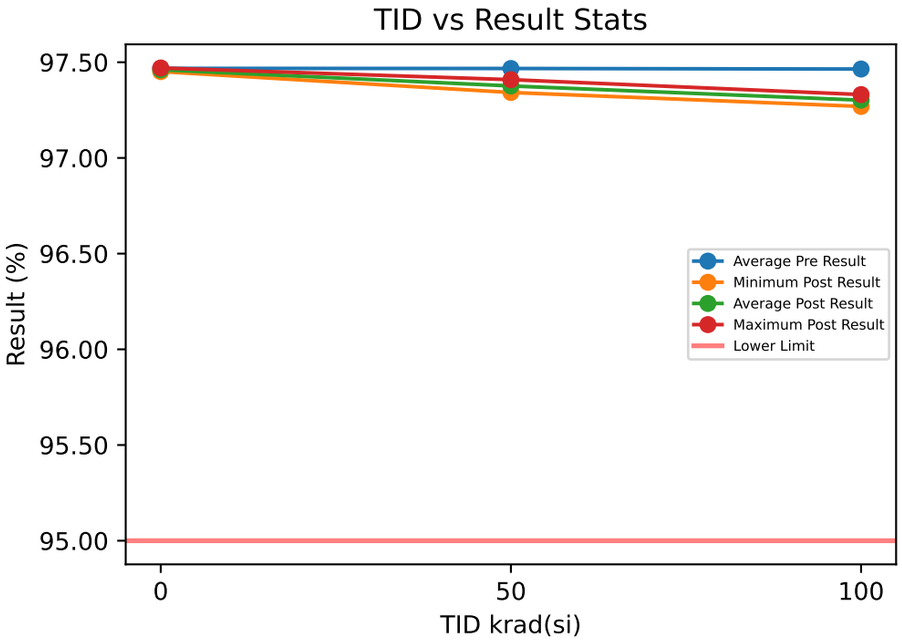
Test Results (Lower Limit = 95.0 (%))

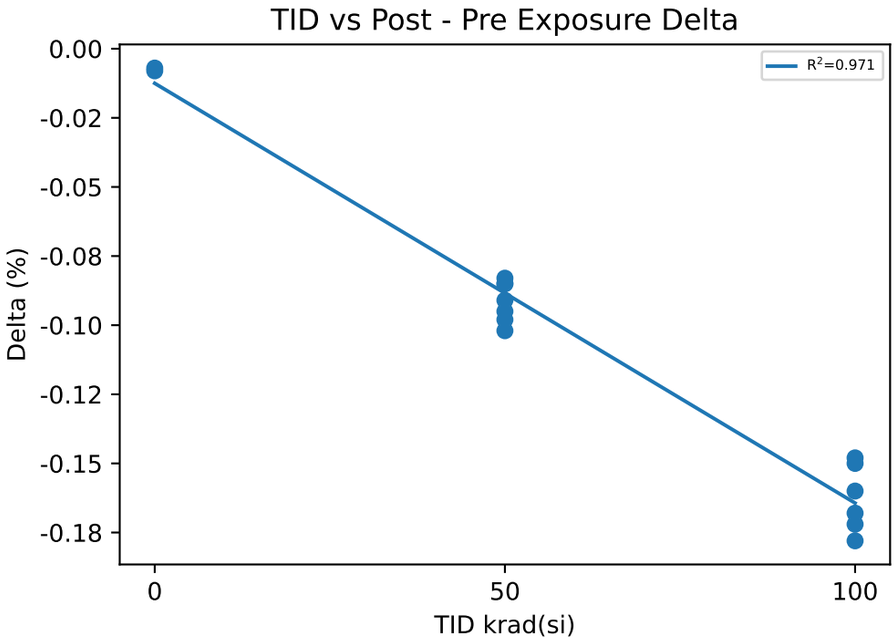
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.807	97.725	-0.082
89	50	Biased	97.824	97.731	-0.093
90	50	Biased	97.809	97.719	-0.09
92	50	Biased	97.78	97.687	-0.093
93	50	Unbiased	97.786	97.668	-0.118
94	50	Unbiased	97.82	97.705	-0.115
95	50	Unbiased	97.792	97.684	-0.108
96	100	Biased	97.814	97.679	-0.135
97	100	Biased	97.793	97.662	-0.131
98	100	Biased	97.801	97.675	-0.126
99	100	Unbiased	97.808	97.643	-0.165
100	100	Unbiased	97.79	97.622	-0.168
101	100	Unbiased	97.788	97.615	-0.173
102	0	Correlation	97.807	97.757	-0.05
103	0	Correlation	97.793	97.745	-0.048

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.793	97.8	97.807	0.0098995	97.745	97.751	97.757	0.0084853	-0.05	-0.049	-0.048	0.0014142
50	97.78	97.803	97.824	0.01693	97.668	97.703	97.731	0.023697	-0.118	-0.099857	-0.082	0.013753
100	97.788	97.799	97.814	0.010469	97.615	97.649	97.679	0.027075	-0.173	-0.14967	-0.126	0.021163

Device Test: 6.51 VOH_WDO_2MA(VOH_2mA_WDOB/WDOB/1.6/14/0/0/2/@VOH_WDO_2MA)





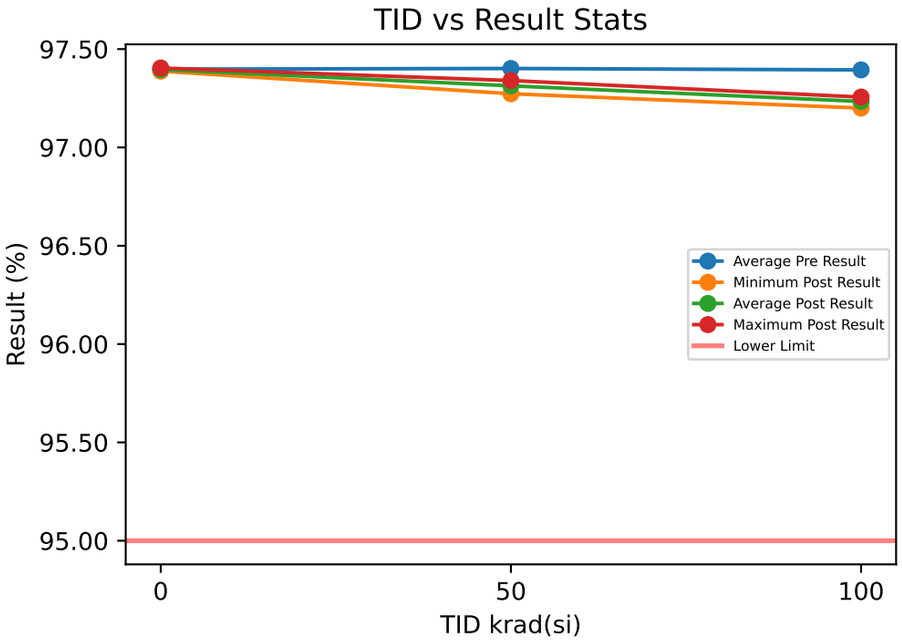
Test Results (Lower Limit = 95.0 (%))

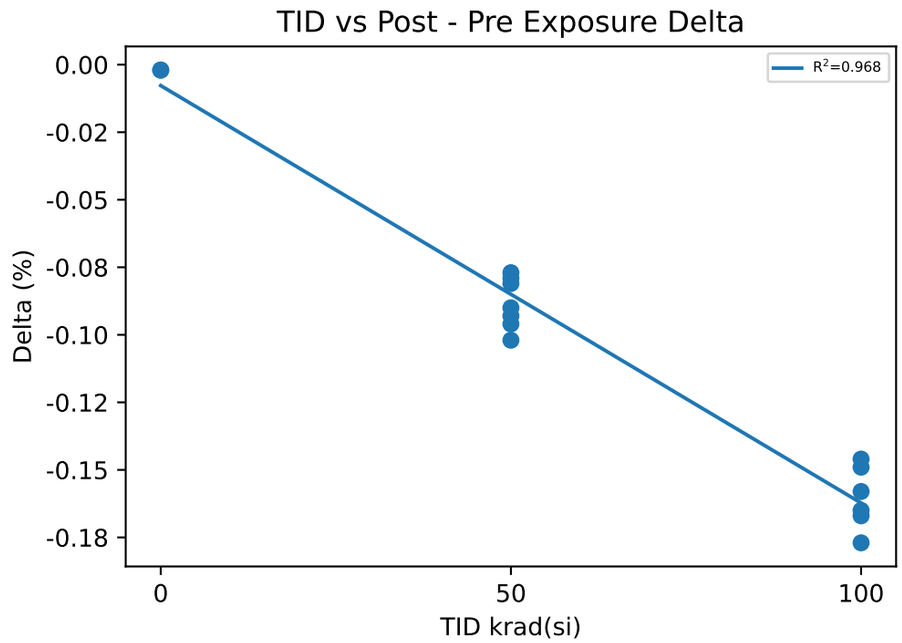
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.477	97.392	-0.085
89	50	Biased	97.492	97.394	-0.098
90	50	Biased	97.475	97.38	-0.095
92	50	Biased	97.444	97.342	-0.102
93	50	Unbiased	97.443	97.352	-0.091
94	50	Unbiased	97.494	97.409	-0.085
95	50	Unbiased	97.446	97.363	-0.083
96	100	Biased	97.484	97.316	-0.168
97	100	Biased	97.447	97.269	-0.178
98	100	Biased	97.463	97.291	-0.172
99	100	Unbiased	97.479	97.331	-0.148
100	100	Unbiased	97.467	97.317	-0.15
101	100	Unbiased	97.447	97.287	-0.16
102	0	Correlation	97.477	97.47	-0.007
103	0	Correlation	97.459	97.451	-0.008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.459	97.468	97.477	0.012728	97.451	97.46	97.47	0.013435	-0.008	-0.0075	-0.007	0.00070711
50	97.443	97.467	97.494	0.022596	97.342	97.376	97.409	0.024447	-0.102	-0.091286	-0.083	0.0073193
100	97.447	97.465	97.484	0.015566	97.269	97.302	97.331	0.023224	-0.178	-0.16267	-0.148	0.012111

Device Test: 6.52 VOH_PWRGD_2MA(VOH_2mA_PWRGD/PWRGD/1.6/14/0/0/2/@VOH_PWRGD_2MA)





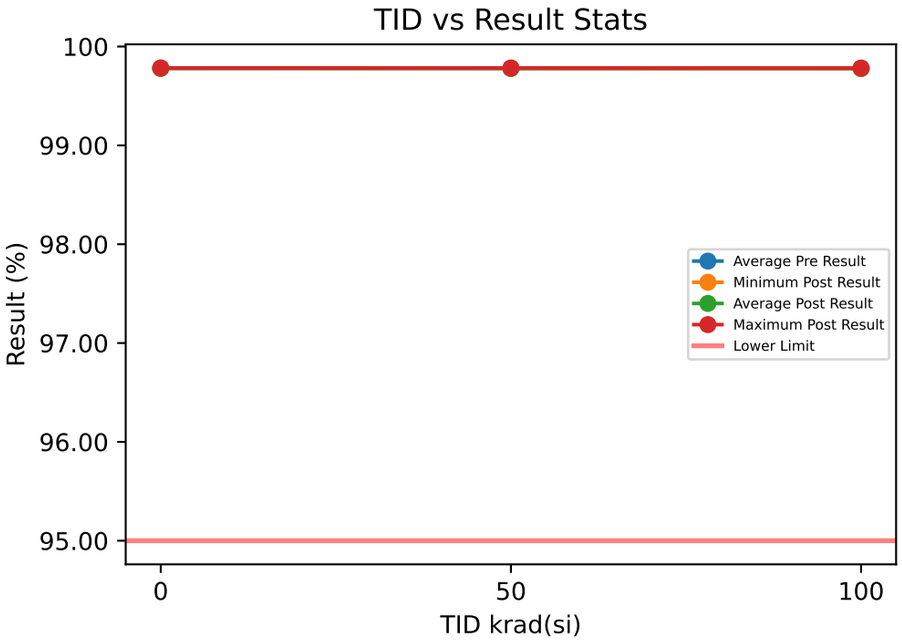
Test Results (Lower Limit = 95.0 (%))

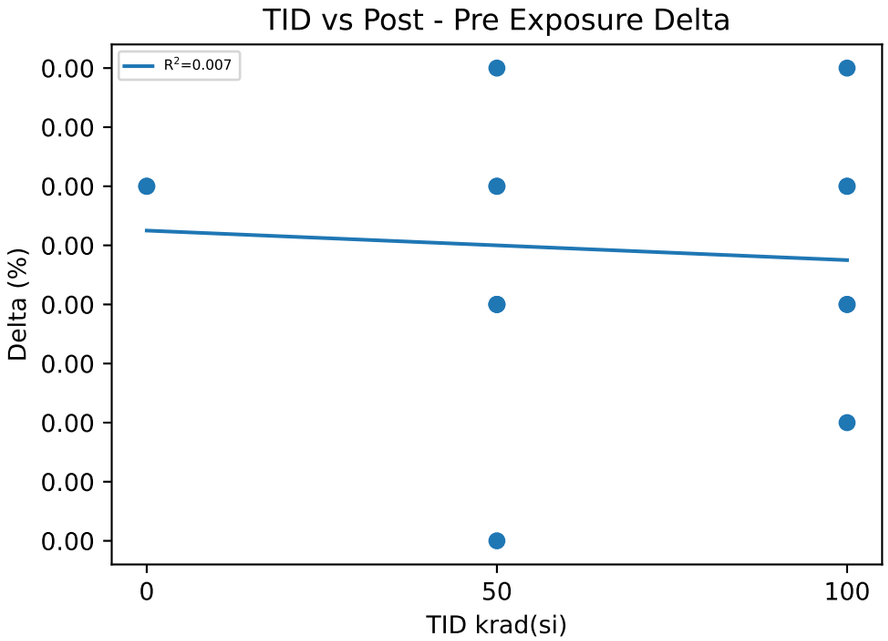
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	97.419	97.34	-0.079
89	50	Biased	97.424	97.328	-0.096
90	50	Biased	97.404	97.311	-0.093
92	50	Biased	97.375	97.273	-0.102
93	50	Unbiased	97.38	97.29	-0.09
94	50	Unbiased	97.421	97.34	-0.081
95	50	Unbiased	97.387	97.31	-0.077
96	100	Biased	97.404	97.239	-0.165
97	100	Biased	97.377	97.2	-0.177
98	100	Biased	97.399	97.232	-0.167
99	100	Unbiased	97.402	97.256	-0.146
100	100	Unbiased	97.394	97.245	-0.149
101	100	Unbiased	97.389	97.231	-0.158
102	0	Correlation	97.406	97.404	-0.002
103	0	Correlation	97.39	97.388	-0.002

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.39	97.398	97.406	0.011314	97.388	97.396	97.404	0.011314	-0.002	-0.002	-0.002	1.0049e-14
50	97.375	97.401	97.424	0.020711	97.273	97.313	97.34	0.025248	-0.102	-0.088286	-0.077	0.0094818
100	97.377	97.394	97.404	0.010028	97.2	97.234	97.256	0.018968	-0.177	-0.16033	-0.146	0.01169

Device Test: 6.53 VOH_RESET_2MA(VOH_2mA_RESETB1/RESETB1/7/3/0/0/2/@VOH_RESET_2MA)





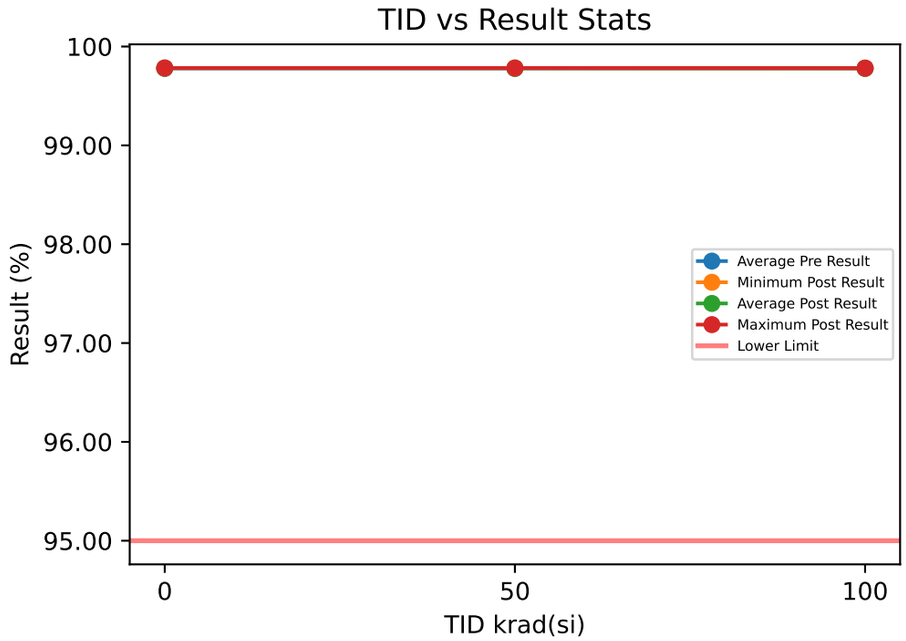
Test Results (Lower Limit = 95.0 (%))

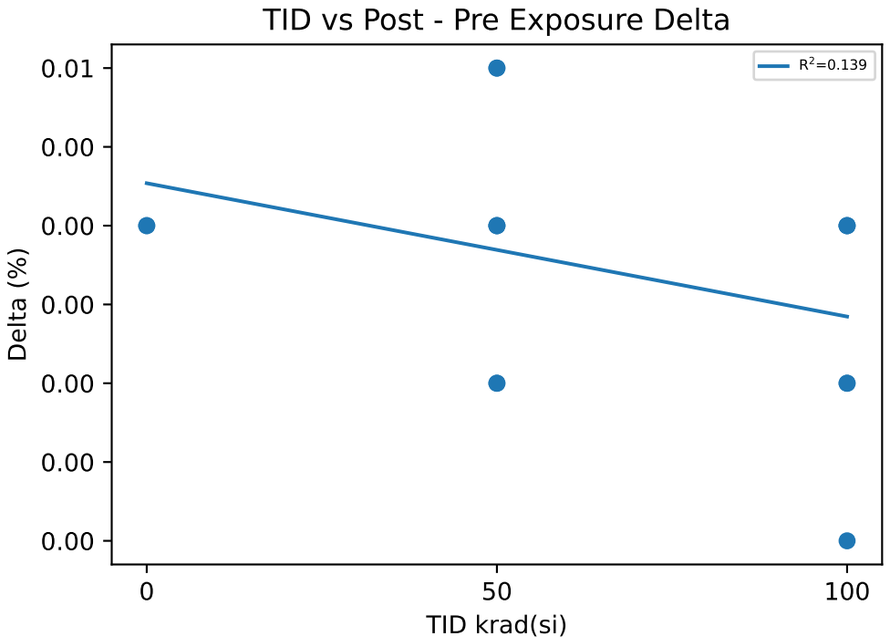
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.777	99.781	0.004
89	50	Biased	99.778	99.78	0.002
90	50	Biased	99.778	99.781	0.003
92	50	Biased	99.777	99.779	0.002
93	50	Unbiased	99.779	99.779	0
94	50	Unbiased	99.778	99.78	0.002
95	50	Unbiased	99.78	99.783	0.003
96	100	Biased	99.776	99.777	0.001
97	100	Biased	99.779	99.781	0.002
98	100	Biased	99.779	99.782	0.003
99	100	Unbiased	99.778	99.782	0.004
100	100	Unbiased	99.777	99.78	0.003
101	100	Unbiased	99.778	99.78	0.002
102	0	Correlation	99.78	99.783	0.003
103	0	Correlation	99.777	99.78	0.003

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.777	99.779	99.78	0.0021213	99.78	99.781	99.783	0.0021213	0.003	0.003	0.003	0
50	99.777	99.778	99.78	0.001069	99.779	99.78	99.783	0.0013973	0	0.0022857	0.004	0.0012536
100	99.776	99.778	99.779	0.001169	99.777	99.78	99.782	0.0018619	0.001	0.0025	0.004	0.0010488

Device Test: 6.54 VOH_RESET_2MA(VOH_2mA_RESETB2/RESETB2/7/3/0/0/2/@VOH_RESET_2MA)





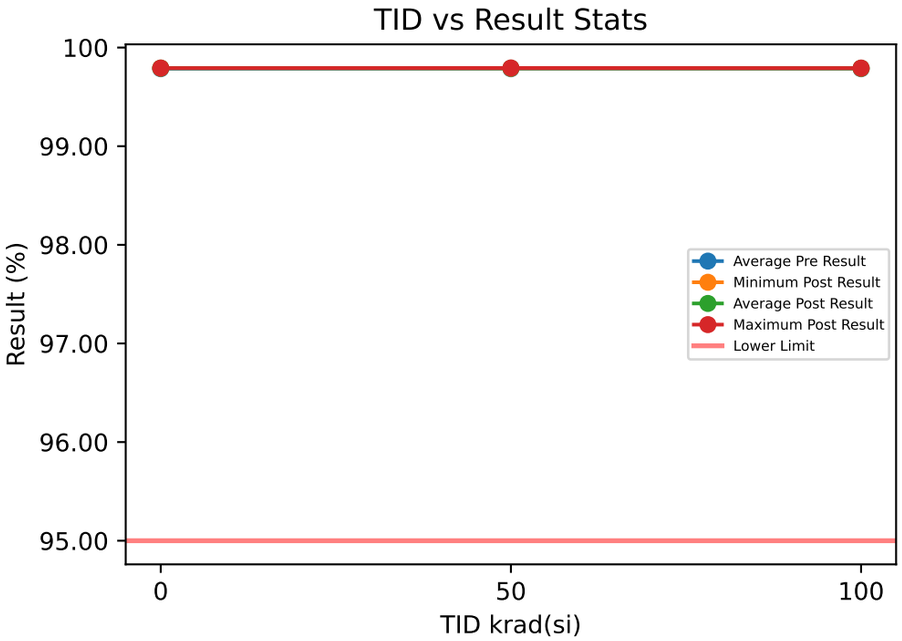
Test Results (Lower Limit = 95.0 (%))

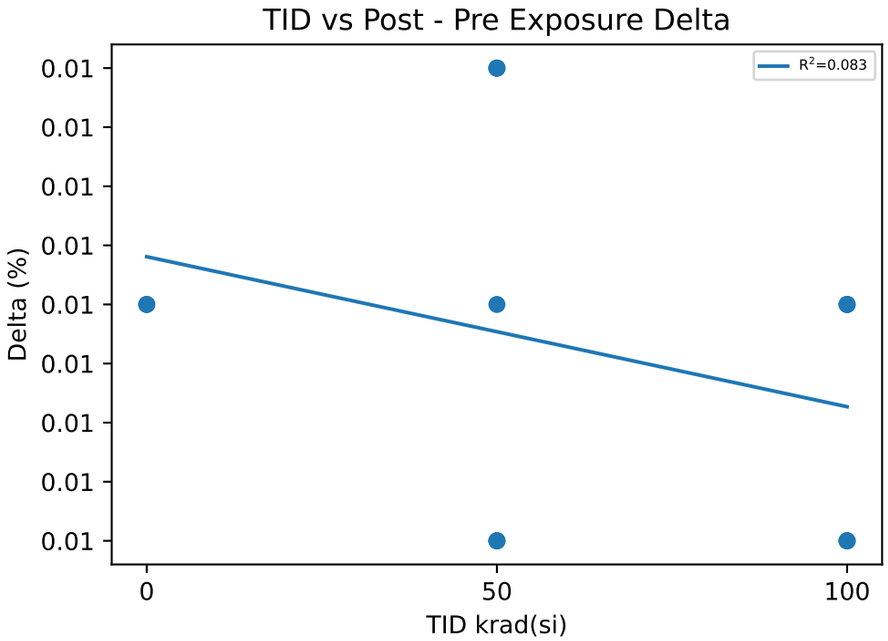
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.778	99.783	0.005
89	50	Biased	99.778	99.782	0.004
90	50	Biased	99.777	99.781	0.004
92	50	Biased	99.777	99.78	0.003
93	50	Unbiased	99.778	99.781	0.003
94	50	Unbiased	99.777	99.781	0.004
95	50	Unbiased	99.778	99.783	0.005
96	100	Biased	99.776	99.779	0.003
97	100	Biased	99.778	99.782	0.004
98	100	Biased	99.779	99.782	0.003
99	100	Unbiased	99.778	99.782	0.004
100	100	Unbiased	99.777	99.781	0.004
101	100	Unbiased	99.779	99.781	0.002
102	0	Correlation	99.779	99.783	0.004
103	0	Correlation	99.777	99.781	0.004

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.777	99.778	99.779	0.0014142	99.781	99.782	99.783	0.0014142	0.004	0.004	0.004	0
50	99.777	99.778	99.778	0.00053452	99.78	99.782	99.783	0.0011339	0.003	0.004	0.005	0.0008165
100	99.776	99.778	99.779	0.001169	99.779	99.781	99.782	0.001169	0.002	0.0033333	0.004	0.0008165

Device Test: 6.55 VOH_RESET_2MA(VOH_2mA_RESETB3/RESETB3/7/3/0/0/2/@VOH_RESET_2MA)





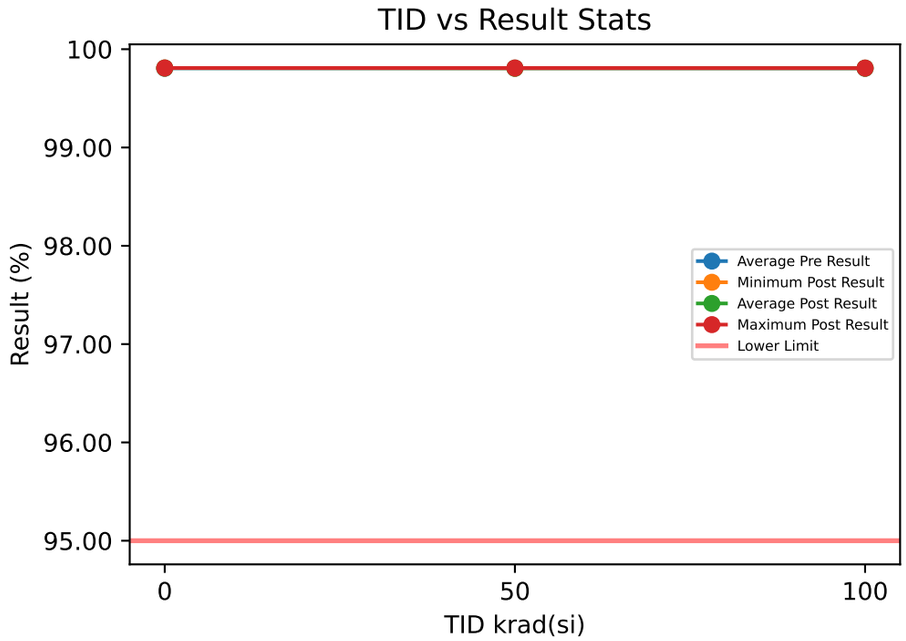
Test Results (Lower Limit = 95.0 (%))

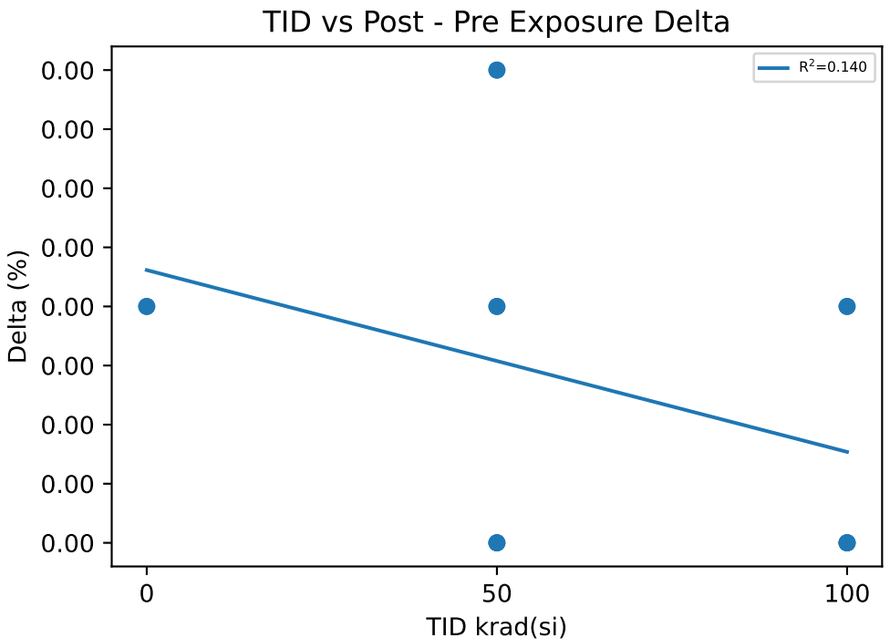
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.786	99.793	0.007
89	50	Biased	99.786	99.791	0.005
90	50	Biased	99.785	99.791	0.006
92	50	Biased	99.784	99.789	0.005
93	50	Unbiased	99.785	99.79	0.005
94	50	Unbiased	99.785	99.792	0.007
95	50	Unbiased	99.785	99.792	0.007
96	100	Biased	99.784	99.789	0.005
97	100	Biased	99.785	99.791	0.006
98	100	Biased	99.787	99.792	0.005
99	100	Unbiased	99.786	99.792	0.006
100	100	Unbiased	99.785	99.791	0.006
101	100	Unbiased	99.785	99.79	0.005
102	0	Correlation	99.786	99.792	0.006
103	0	Correlation	99.785	99.791	0.006

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.785	99.785	99.786	0.00070711	99.791	99.791	99.792	0.00070711	0.006	0.006	0.006	0
50	99.784	99.785	99.786	0.00069007	99.789	99.791	99.793	0.0013452	0.005	0.006	0.007	0.001
100	99.784	99.785	99.787	0.0010328	99.789	99.791	99.792	0.001169	0.005	0.0055	0.006	0.00054772

Device Test: 6.56 VOH_RESET_2MA(VOH_2mA_RESETB4/RESETB4/7/3/0/0/2/@VOH_RESET_2MA)





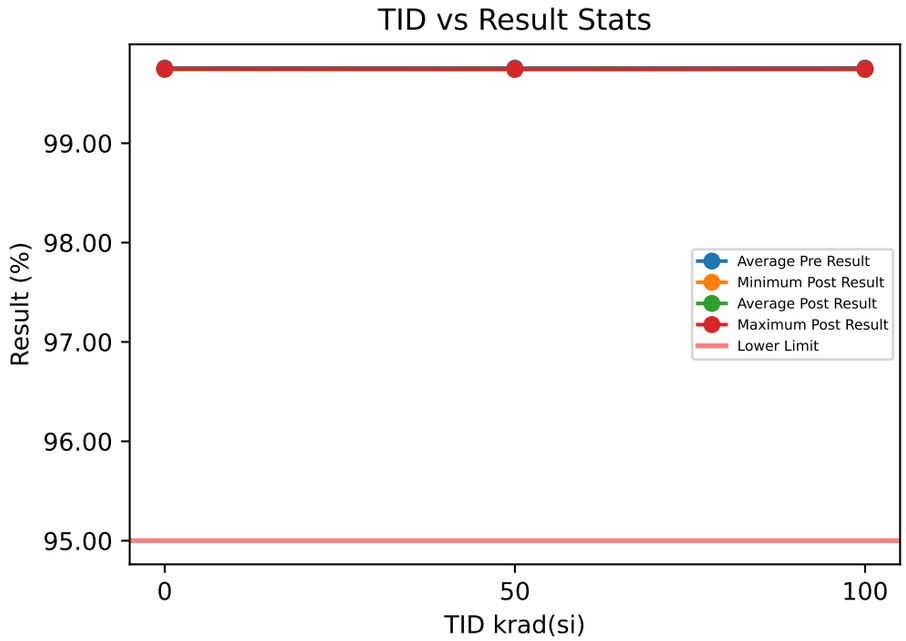
Test Results (Lower Limit = 95.0 (%))

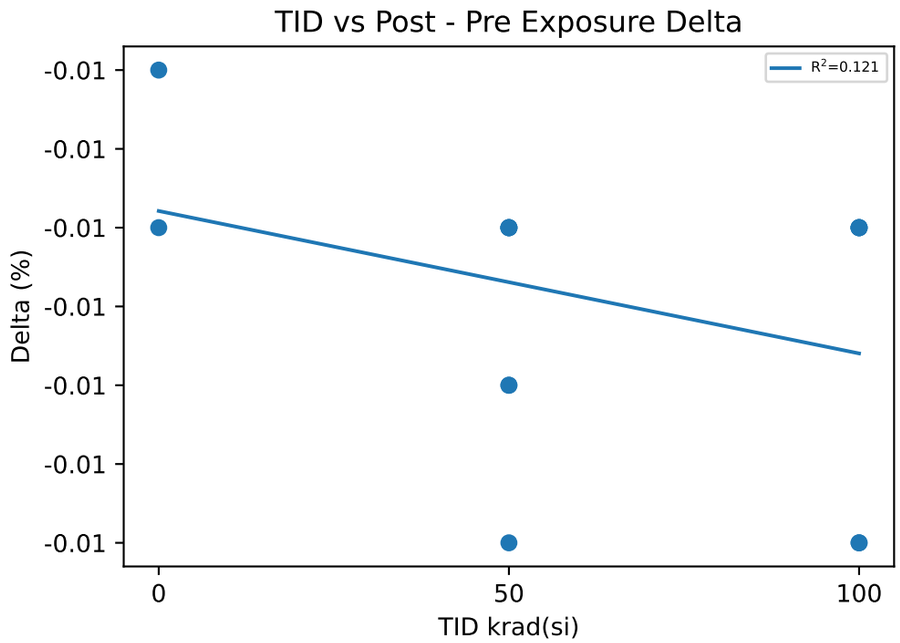
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.805	99.809	0.004
89	50	Biased	99.805	99.808	0.003
90	50	Biased	99.806	99.808	0.002
92	50	Biased	99.804	99.806	0.002
93	50	Unbiased	99.805	99.807	0.002
94	50	Unbiased	99.805	99.808	0.003
95	50	Unbiased	99.805	99.809	0.004
96	100	Biased	99.805	99.807	0.002
97	100	Biased	99.805	99.808	0.003
98	100	Biased	99.806	99.808	0.002
99	100	Unbiased	99.805	99.808	0.003
100	100	Unbiased	99.805	99.807	0.002
101	100	Unbiased	99.805	99.807	0.002
102	0	Correlation	99.806	99.809	0.003
103	0	Correlation	99.805	99.808	0.003

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.805	99.805	99.806	0.00070711	99.808	99.809	99.809	0.00070711	0.003	0.003	0.003	0
50	99.804	99.805	99.806	0.00057735	99.806	99.808	99.809	0.001069	0.002	0.0028571	0.004	0.00089974
100	99.805	99.805	99.806	0.00040825	99.807	99.808	99.808	0.00054772	0.002	0.0023333	0.003	0.0005164

Device Test: 6.57 VOH_WDO_2MA(VOH_2mA_WDOB/WDOB/7/3/0/0/2/@VOH_WDO_2MA)





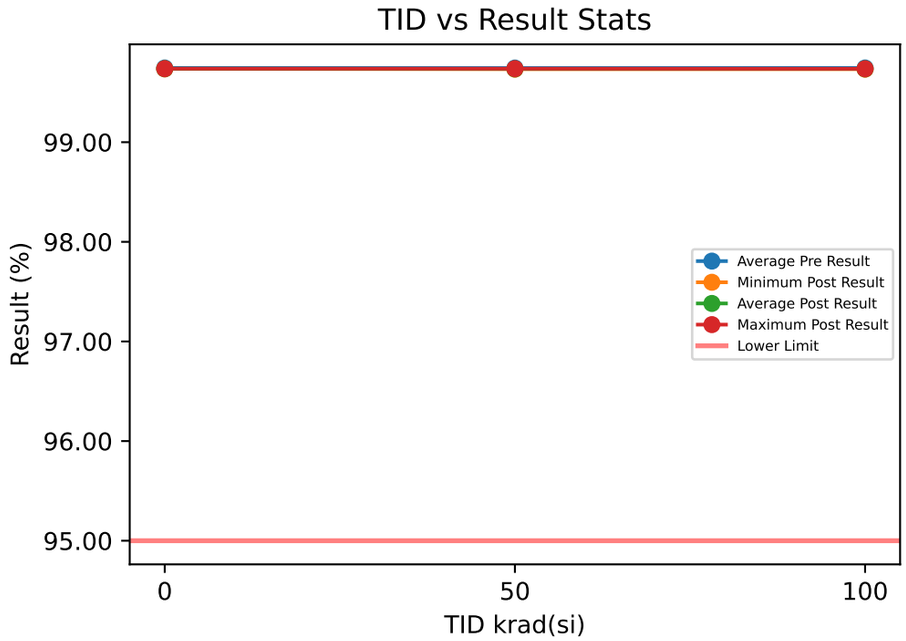
Test Results (Lower Limit = 95.0 (%))

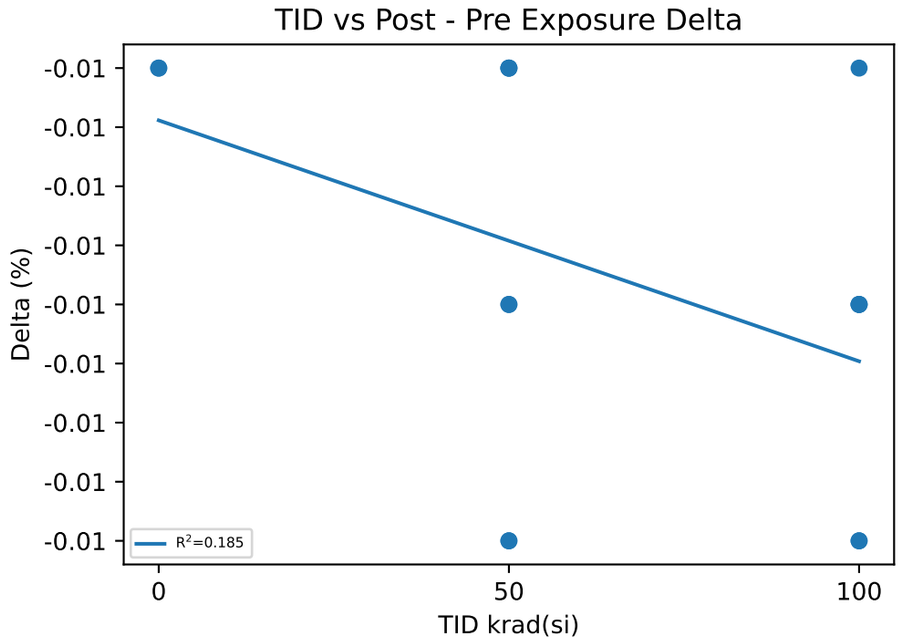
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.758	99.745	-0.013
89	50	Biased	99.756	99.744	-0.012
90	50	Biased	99.757	99.745	-0.012
92	50	Biased	99.754	99.742	-0.012
93	50	Unbiased	99.756	99.742	-0.014
94	50	Unbiased	99.757	99.745	-0.012
95	50	Unbiased	99.757	99.744	-0.013
96	100	Biased	99.756	99.742	-0.014
97	100	Biased	99.757	99.745	-0.012
98	100	Biased	99.757	99.745	-0.012
99	100	Unbiased	99.758	99.746	-0.012
100	100	Unbiased	99.757	99.745	-0.012
101	100	Unbiased	99.757	99.743	-0.014
102	0	Correlation	99.758	99.747	-0.011
103	0	Correlation	99.755	99.743	-0.012

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.755	99.756	99.758	0.0021213	99.743	99.745	99.747	0.0028284	-0.012	-0.0115	-0.011	0.00070711
50	99.754	99.756	99.758	0.0012724	99.742	99.744	99.745	0.0013452	-0.014	-0.012571	-0.012	0.0007868
100	99.756	99.757	99.758	0.00063246	99.742	99.744	99.746	0.0015055	-0.014	-0.012667	-0.012	0.0010328

Device Test: 6.58 VOH_PWRGD_2MA(VOH_2mA_PWRGD/PWRGD/7/3/0/0/2/@VOH_PWRGD_2MA)





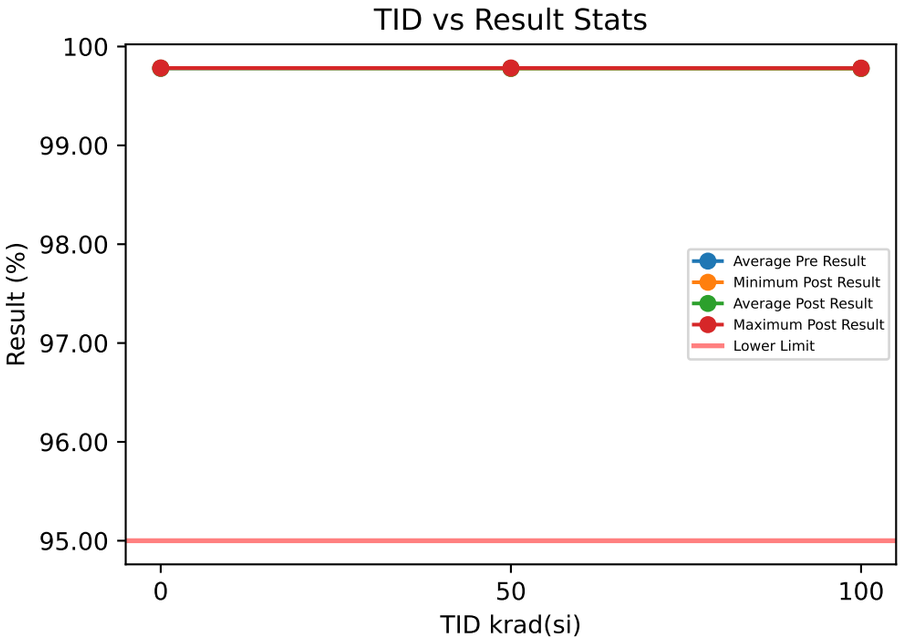
Test Results (Lower Limit = 95.0 (%))

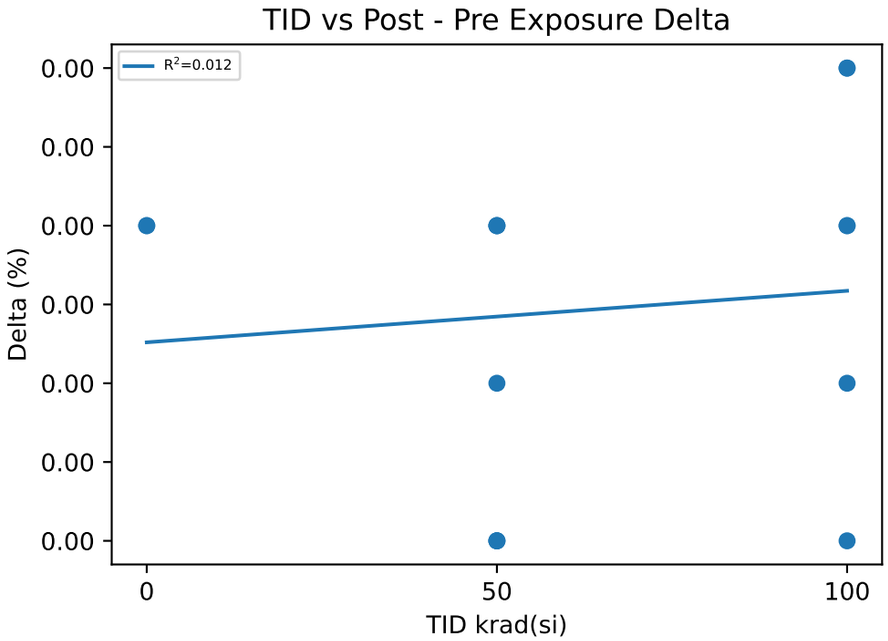
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.746	99.738	-0.008
89	50	Biased	99.745	99.735	-0.01
90	50	Biased	99.745	99.736	-0.009
92	50	Biased	99.742	99.733	-0.009
93	50	Unbiased	99.744	99.734	-0.01
94	50	Unbiased	99.744	99.736	-0.008
95	50	Unbiased	99.745	99.737	-0.008
96	100	Biased	99.743	99.733	-0.01
97	100	Biased	99.745	99.736	-0.009
98	100	Biased	99.746	99.737	-0.009
99	100	Unbiased	99.745	99.737	-0.008
100	100	Unbiased	99.745	99.736	-0.009
101	100	Unbiased	99.746	99.736	-0.01
102	0	Correlation	99.746	99.738	-0.008
103	0	Correlation	99.744	99.736	-0.008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.744	99.745	99.746	0.0014142	99.736	99.737	99.738	0.0014142	-0.008	-0.008	-0.008	0
50	99.742	99.744	99.746	0.0012724	99.733	99.736	99.738	0.0017182	-0.01	-0.0088571	-0.008	0.00089974
100	99.743	99.745	99.746	0.0010954	99.733	99.736	99.737	0.001472	-0.01	-0.0091667	-0.008	0.00075277

Device Test: 6.59 VOH_RESET_2MA(VOH_2mA_RESETB1/RESETB1/7/14/0/0/2/@VOH_RESET_2MA)





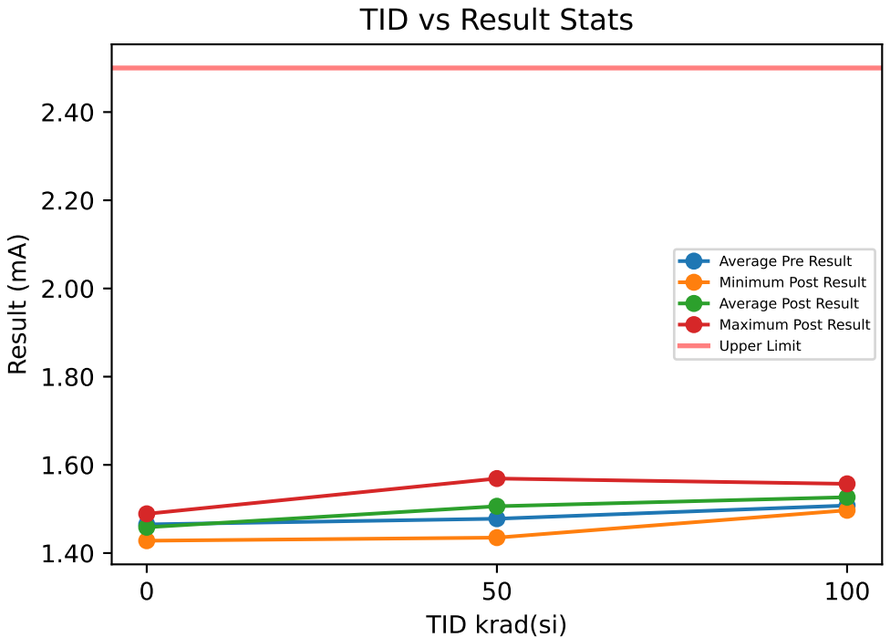
Test Results (Lower Limit = 95.0 (%))

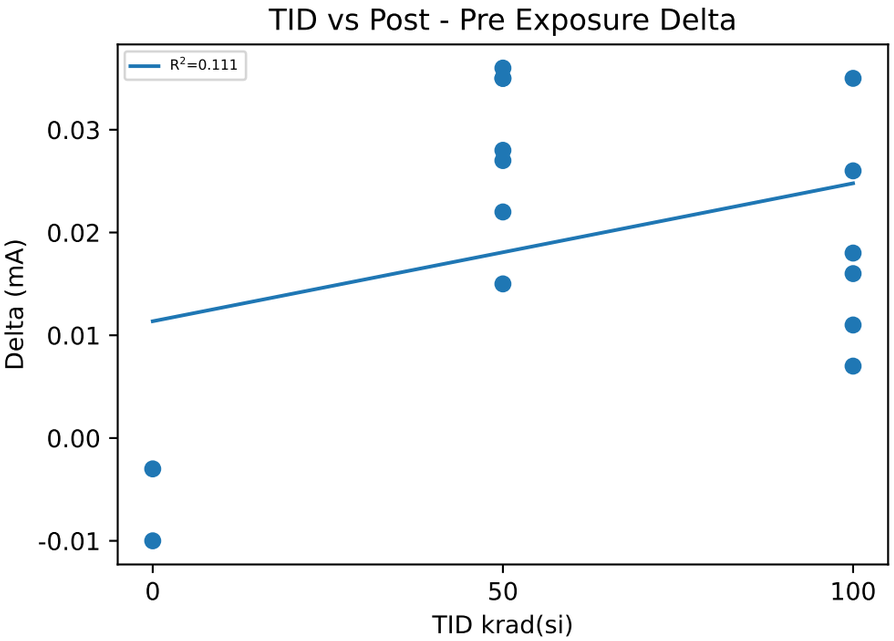
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.778	99.781	0.003
89	50	Biased	99.778	99.78	0.002
90	50	Biased	99.778	99.781	0.003
92	50	Biased	99.777	99.778	0.001
93	50	Unbiased	99.779	99.78	0.001
94	50	Unbiased	99.778	99.779	0.001
95	50	Unbiased	99.78	99.783	0.003
96	100	Biased	99.776	99.777	0.001
97	100	Biased	99.778	99.781	0.003
98	100	Biased	99.778	99.782	0.004
99	100	Unbiased	99.777	99.781	0.004
100	100	Unbiased	99.777	99.78	0.003
101	100	Unbiased	99.778	99.78	0.002
102	0	Correlation	99.78	99.783	0.003
103	0	Correlation	99.777	99.78	0.003

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.777	99.779	99.78	0.0021213	99.78	99.781	99.783	0.0021213	0.003	0.003	0.003	0
50	99.777	99.778	99.78	0.00095119	99.778	99.78	99.783	0.0016036	0.001	0.002	0.003	0.001
100	99.776	99.777	99.778	0.0008165	99.777	99.78	99.782	0.0017224	0.001	0.0028333	0.004	0.001169

Device Test: 6.6 IQ(IQ3_High/IN//3/0/0/0/@IQ)





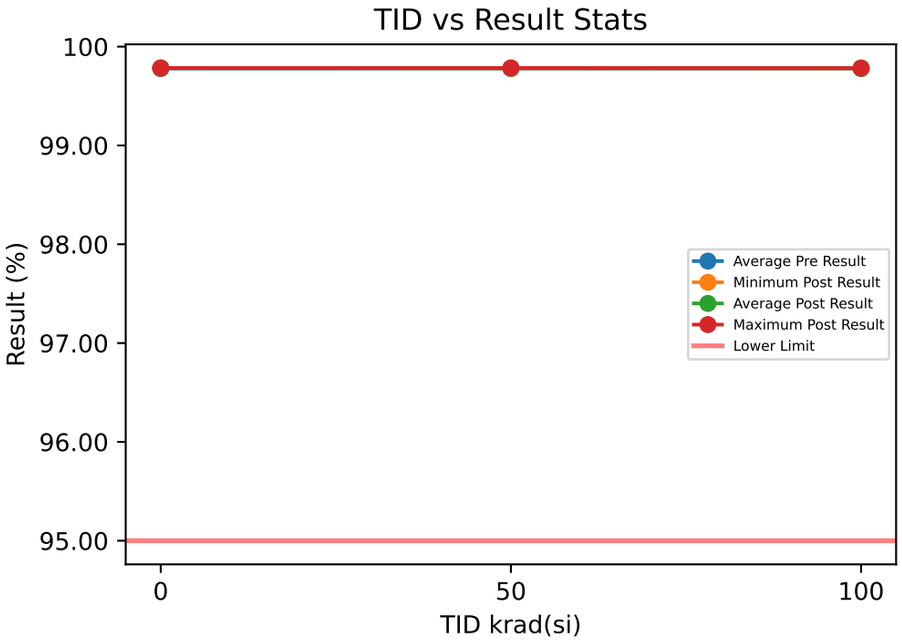
Test Results (Upper Limit = 2.5 (mA))

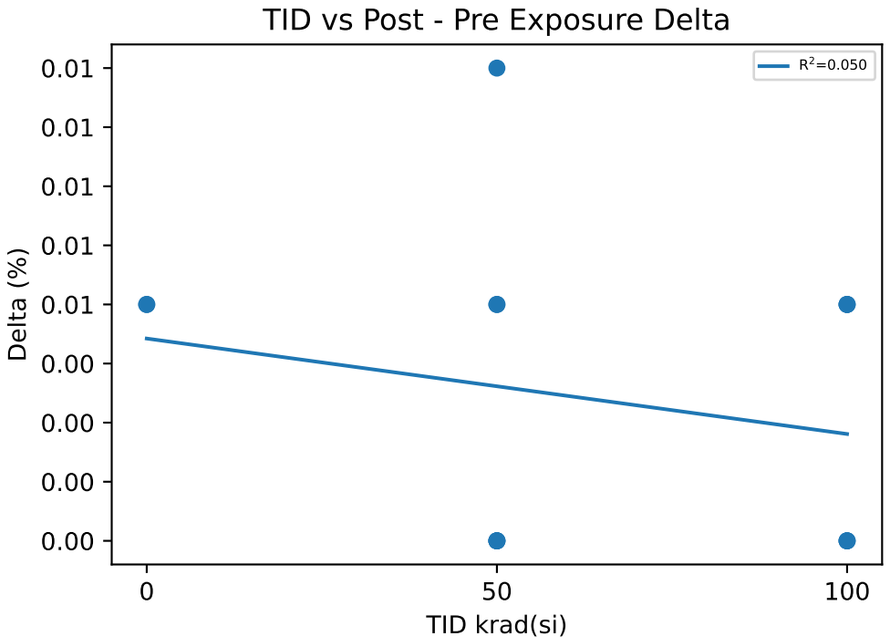
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.462	1.497	0.035
89	50	Biased	1.523	1.551	0.028
90	50	Biased	1.533	1.569	0.036
92	50	Biased	1.481	1.496	0.015
93	50	Unbiased	1.46	1.482	0.022
94	50	Unbiased	1.478	1.513	0.035
95	50	Unbiased	1.408	1.435	0.027
96	100	Biased	1.546	1.557	0.011
97	100	Biased	1.462	1.497	0.035
98	100	Biased	1.516	1.523	0.007
99	100	Unbiased	1.524	1.542	0.018
100	100	Unbiased	1.499	1.515	0.016
101	100	Unbiased	1.5	1.526	0.026
102	0	Correlation	1.492	1.489	-0.003
103	0	Correlation	1.438	1.428	-0.01

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.438	1.465	1.492	0.038184	1.428	1.4585	1.489	0.043134	-0.01	-0.0065	-0.003	0.0049497
50	1.408	1.4779	1.533	0.04191	1.435	1.5061	1.569	0.044424	0.015	0.028286	0.036	0.0078255
100	1.462	1.5078	1.546	0.028372	1.497	1.5267	1.557	0.020906	0.007	0.018833	0.035	0.010226

Device Test: 6.60 VOH_RESET_2MA(VOH_2mA_RESETB2/RESETB2/7/14/0/0/2/@VOH_RESET_2MA)





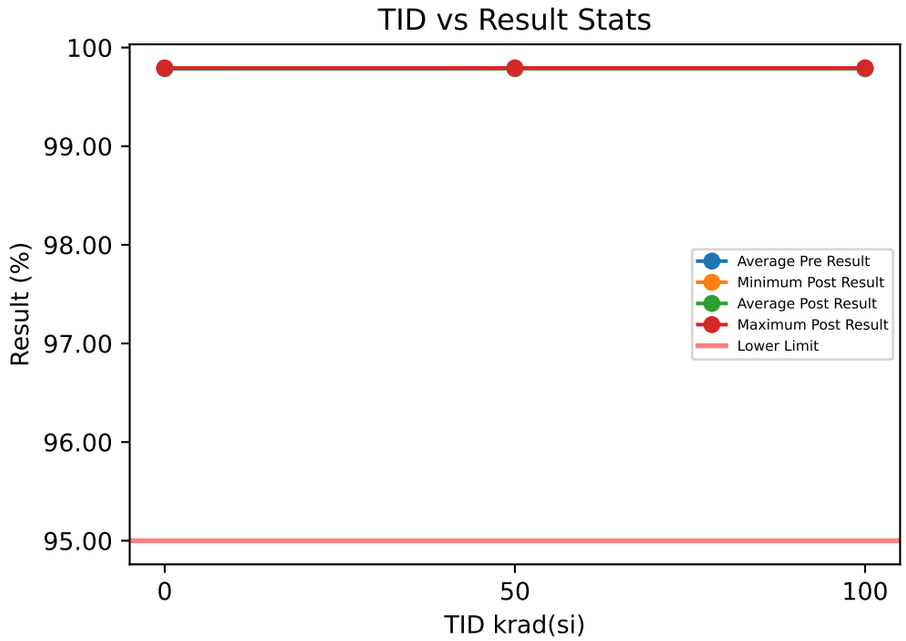
Test Results (Lower Limit = 95.0 (%))

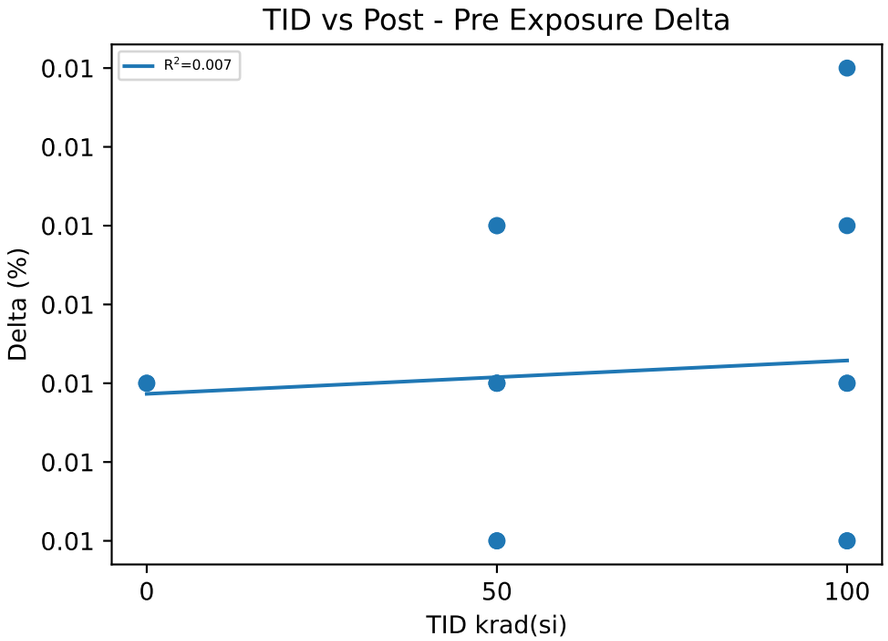
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.778	99.784	0.006
89	50	Biased	99.778	99.783	0.005
90	50	Biased	99.777	99.782	0.005
92	50	Biased	99.777	99.781	0.004
93	50	Unbiased	99.778	99.782	0.004
94	50	Unbiased	99.778	99.782	0.004
95	50	Unbiased	99.779	99.783	0.004
96	100	Biased	99.776	99.78	0.004
97	100	Biased	99.777	99.782	0.005
98	100	Biased	99.778	99.783	0.005
99	100	Unbiased	99.778	99.783	0.005
100	100	Unbiased	99.778	99.782	0.004
101	100	Unbiased	99.779	99.783	0.004
102	0	Correlation	99.779	99.784	0.005
103	0	Correlation	99.777	99.782	0.005

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.777	99.778	99.779	0.0014142	99.782	99.783	99.784	0.0014142	0.005	0.005	0.005	1.0049e-14
50	99.777	99.778	99.779	0.00069007	99.781	99.782	99.784	0.0009759	0.004	0.0045714	0.006	0.0007868
100	99.776	99.778	99.779	0.0010328	99.78	99.782	99.783	0.001169	0.004	0.0045	0.005	0.00054772

Device Test: 6.61 VOH_RESET_2MA(VOH_2mA_RESETB3/RESETB3/7/14/0/0/2/@VOH_RESET_2MA)





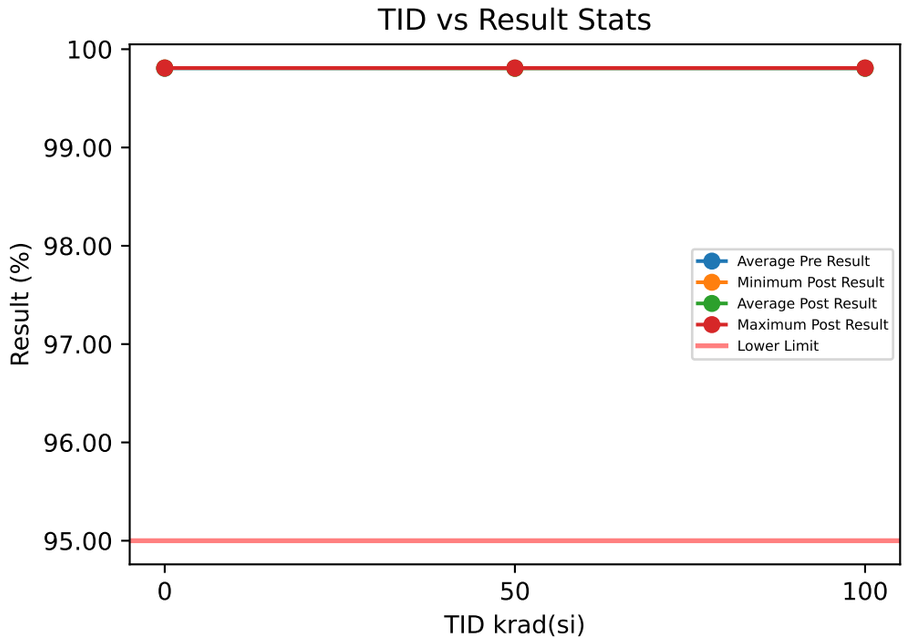
Test Results (Lower Limit = 95.0 (%))

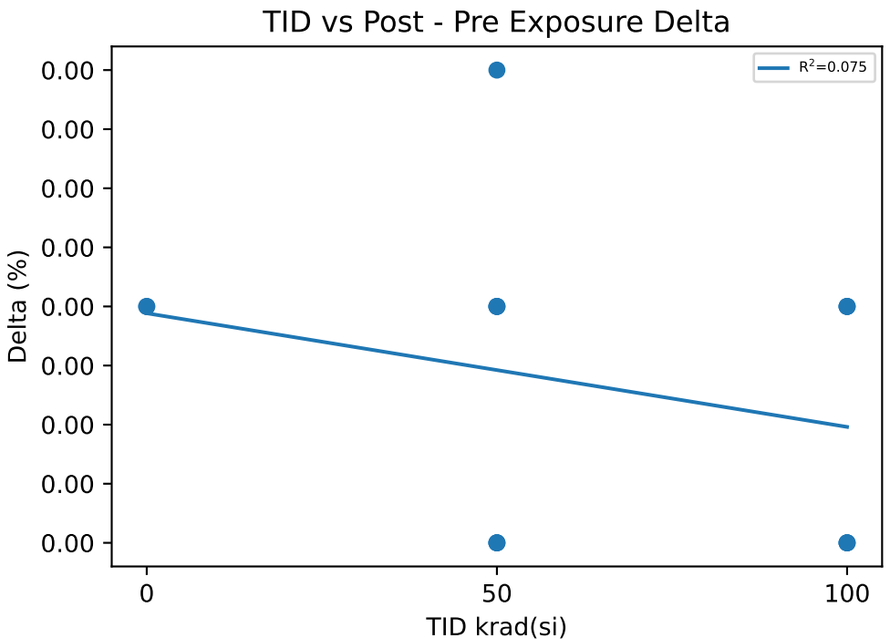
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.786	99.793	0.007
89	50	Biased	99.786	99.791	0.005
90	50	Biased	99.785	99.791	0.006
92	50	Biased	99.784	99.789	0.005
93	50	Unbiased	99.785	99.791	0.006
94	50	Unbiased	99.785	99.791	0.006
95	50	Unbiased	99.785	99.792	0.007
96	100	Biased	99.784	99.789	0.005
97	100	Biased	99.785	99.792	0.007
98	100	Biased	99.786	99.792	0.006
99	100	Unbiased	99.785	99.793	0.008
100	100	Unbiased	99.785	99.791	0.006
101	100	Unbiased	99.785	99.79	0.005
102	0	Correlation	99.786	99.792	0.006
103	0	Correlation	99.785	99.791	0.006

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.785	99.785	99.786	0.00070711	99.791	99.791	99.792	0.00070711	0.006	0.006	0.006	0
50	99.784	99.785	99.786	0.00069007	99.789	99.791	99.793	0.001215	0.005	0.006	0.007	0.0008165
100	99.784	99.785	99.786	0.00063246	99.789	99.791	99.793	0.001472	0.005	0.0061667	0.008	0.001169

Device Test: 6.62 VOH_RESET_2MA(VOH_2mA_RESETB4/RESETB4/7/14/0/0/2/@VOH_RESET_2MA)





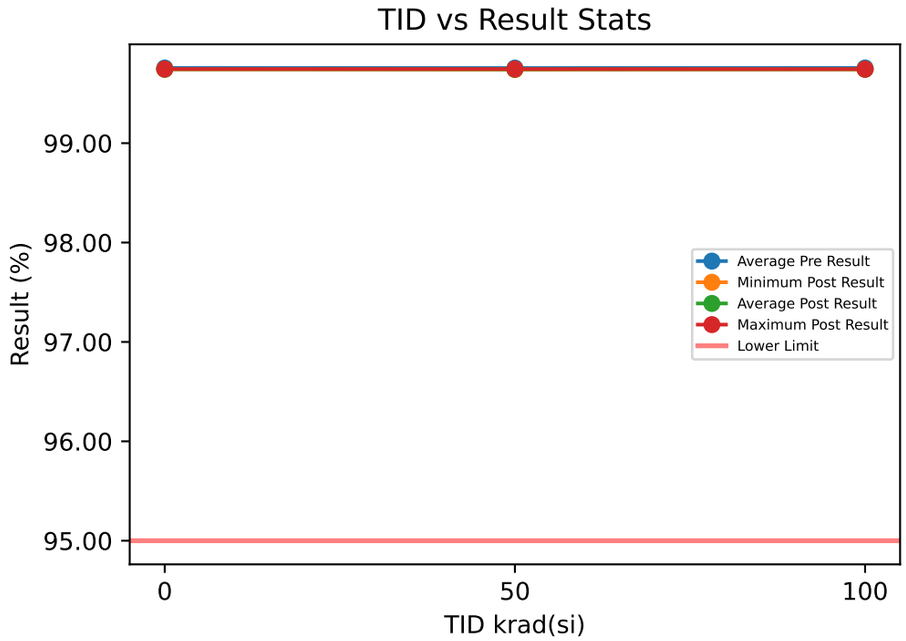
Test Results (Lower Limit = 95.0 (%))

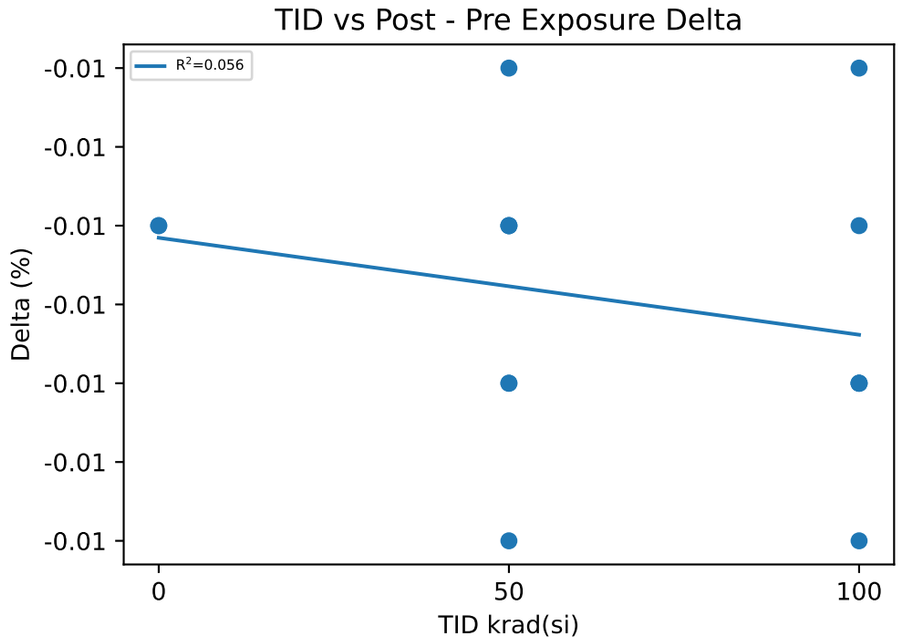
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.806	99.809	0.003
89	50	Biased	99.806	99.808	0.002
90	50	Biased	99.805	99.808	0.003
92	50	Biased	99.804	99.806	0.002
93	50	Unbiased	99.805	99.807	0.002
94	50	Unbiased	99.805	99.808	0.003
95	50	Unbiased	99.805	99.809	0.004
96	100	Biased	99.805	99.807	0.002
97	100	Biased	99.805	99.808	0.003
98	100	Biased	99.806	99.809	0.003
99	100	Unbiased	99.805	99.808	0.003
100	100	Unbiased	99.805	99.807	0.002
101	100	Unbiased	99.805	99.807	0.002
102	0	Correlation	99.806	99.809	0.003
103	0	Correlation	99.805	99.808	0.003

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.805	99.805	99.806	0.00070711	99.808	99.809	99.809	0.00070711	0.003	0.003	0.003	0
50	99.804	99.805	99.806	0.00069007	99.806	99.808	99.809	0.001069	0.002	0.0027143	0.004	0.00075593
100	99.805	99.805	99.806	0.00040825	99.807	99.808	99.809	0.0008165	0.002	0.0025	0.003	0.00054772

Device Test: 6.63 VOH_WDO_2MA(VOH_2mA_WDOB/WDOB/7/14/0/0/2/@VOH_WDO_2MA)





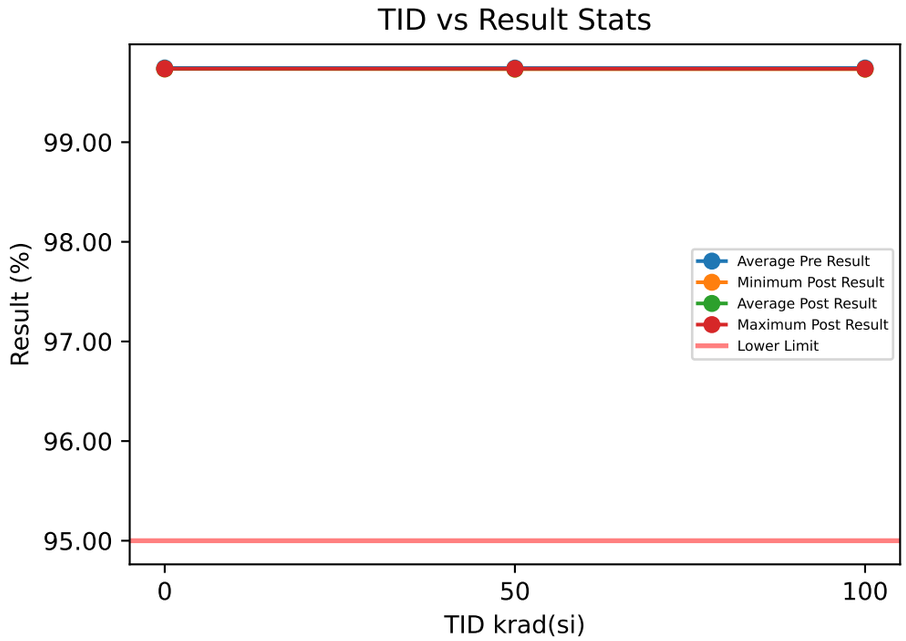
Test Results (Lower Limit = 95.0 (%))

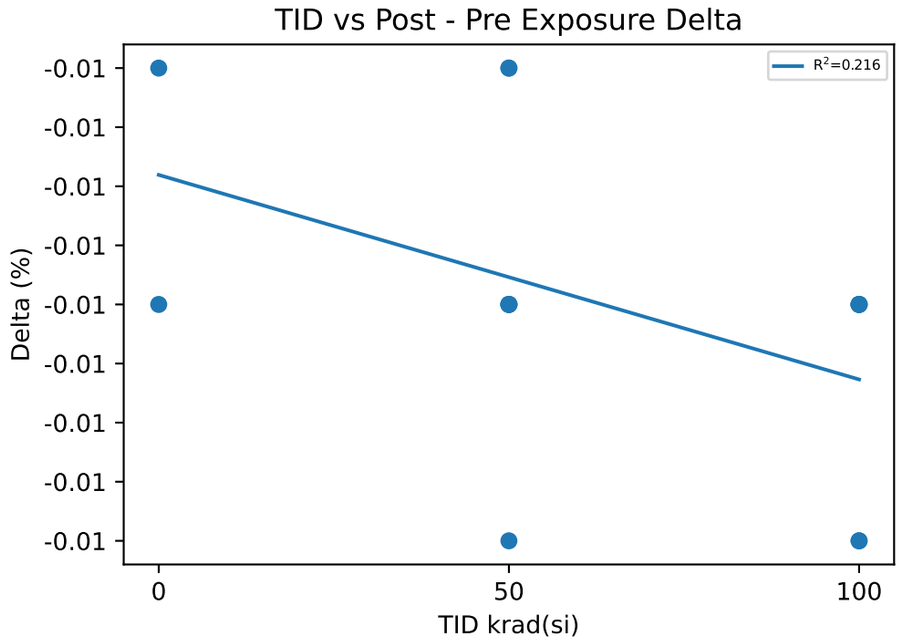
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.757	99.746	-0.011
89	50	Biased	99.756	99.744	-0.012
90	50	Biased	99.757	99.744	-0.013
92	50	Biased	99.754	99.741	-0.013
93	50	Unbiased	99.756	99.742	-0.014
94	50	Unbiased	99.756	99.744	-0.012
95	50	Unbiased	99.756	99.744	-0.012
96	100	Biased	99.756	99.743	-0.013
97	100	Biased	99.757	99.743	-0.014
98	100	Biased	99.756	99.745	-0.011
99	100	Unbiased	99.758	99.745	-0.013
100	100	Unbiased	99.757	99.744	-0.013
101	100	Unbiased	99.756	99.744	-0.012
102	0	Correlation	99.758	99.746	-0.012
103	0	Correlation	99.755	99.743	-0.012

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.755	99.756	99.758	0.0021213	99.743	99.744	99.746	0.0021213	-0.012	-0.012	-0.012	0
50	99.754	99.756	99.757	0.001	99.741	99.744	99.746	0.0016183	-0.014	-0.012429	-0.011	0.0009759
100	99.756	99.757	99.758	0.0008165	99.743	99.744	99.745	0.00089443	-0.014	-0.012667	-0.011	0.0010328

Device Test: 6.64 VOH_PWRGD_2MA(VOH_2mA_PWRGD/PWRGD/7/14/0/0/2/@VOH_PWRGD_2MA)





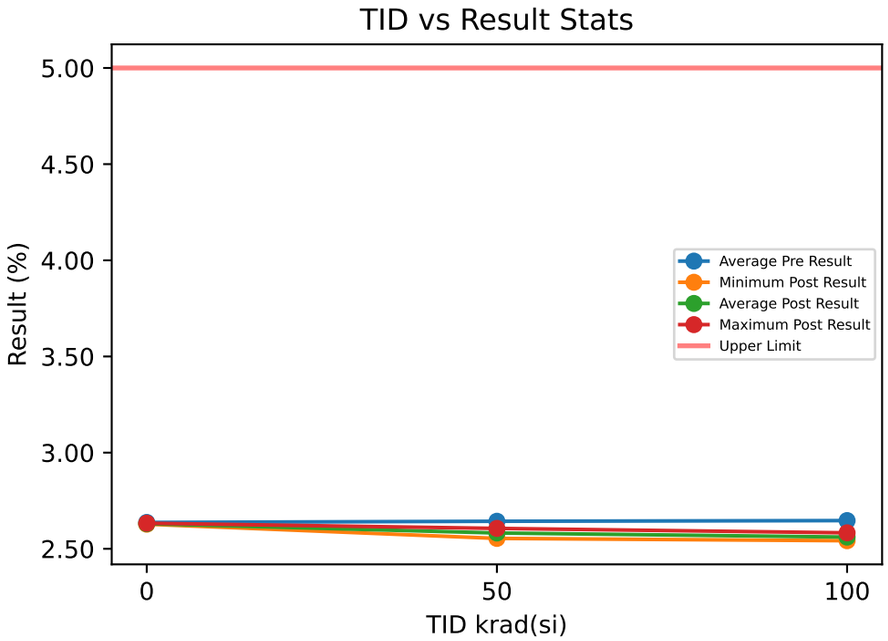
Test Results (Lower Limit = 95.0 (%))

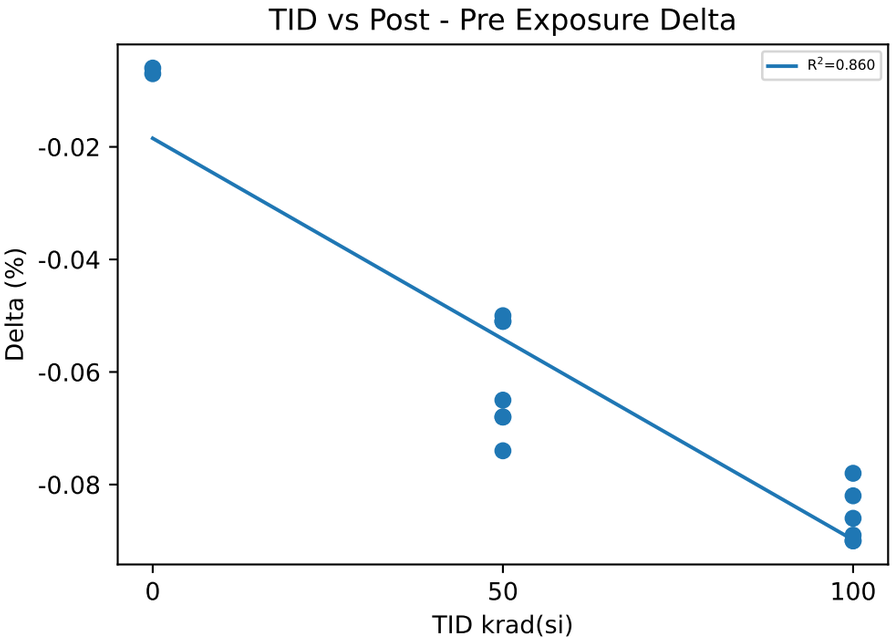
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.746	99.738	-0.008
89	50	Biased	99.744	99.734	-0.01
90	50	Biased	99.744	99.736	-0.008
92	50	Biased	99.742	99.733	-0.009
93	50	Unbiased	99.744	99.735	-0.009
94	50	Unbiased	99.744	99.735	-0.009
95	50	Unbiased	99.745	99.736	-0.009
96	100	Biased	99.742	99.733	-0.009
97	100	Biased	99.744	99.735	-0.009
98	100	Biased	99.746	99.737	-0.009
99	100	Unbiased	99.745	99.736	-0.009
100	100	Unbiased	99.745	99.735	-0.01
101	100	Unbiased	99.746	99.736	-0.01
102	0	Correlation	99.746	99.738	-0.008
103	0	Correlation	99.744	99.735	-0.009

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.744	99.745	99.746	0.0014142	99.735	99.737	99.738	0.0021213	-0.009	-0.0085	-0.008	0.00070711
50	99.742	99.744	99.746	0.001215	99.733	99.735	99.738	0.0016036	-0.01	-0.0088571	-0.008	0.00069007
100	99.742	99.745	99.746	0.0015055	99.733	99.735	99.737	0.0013663	-0.01	-0.0093333	-0.009	0.0005164

Device Test: 6.65 VOL_RESET_2MA(VOL_2mA_RESETB1/RESETB1/1.6/3/0/0/2/@VOL_RESET_2MA)





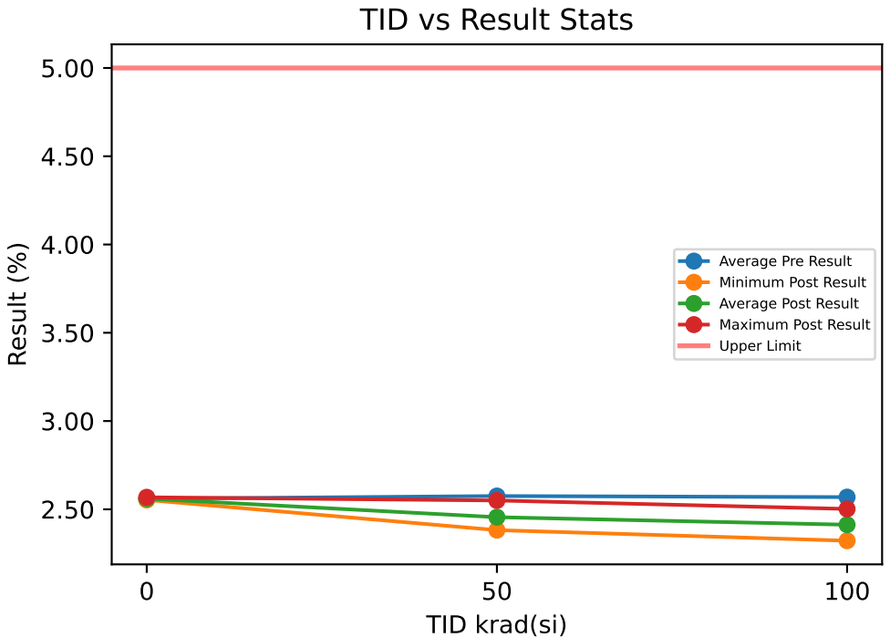
Test Results (Upper Limit = 5.0 (%))

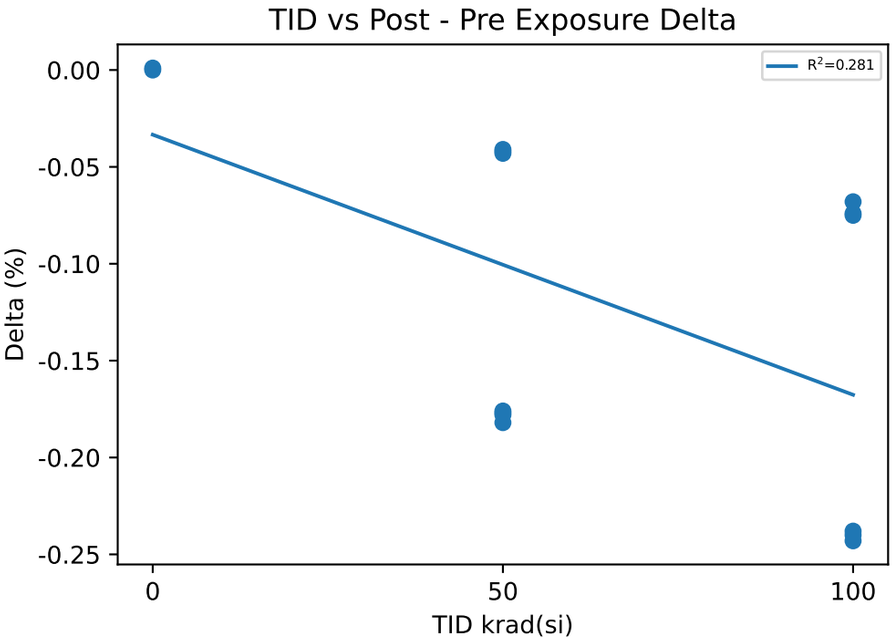
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.628	2.554	-0.074
89	50	Biased	2.644	2.576	-0.068
90	50	Biased	2.651	2.583	-0.068
92	50	Biased	2.631	2.566	-0.065
93	50	Unbiased	2.649	2.599	-0.05
94	50	Unbiased	2.657	2.606	-0.051
95	50	Unbiased	2.642	2.591	-0.051
96	100	Biased	2.659	2.57	-0.089
97	100	Biased	2.632	2.542	-0.09
98	100	Biased	2.634	2.544	-0.09
99	100	Unbiased	2.669	2.583	-0.086
100	100	Unbiased	2.64	2.558	-0.082
101	100	Unbiased	2.646	2.568	-0.078
102	0	Correlation	2.634	2.628	-0.006
103	0	Correlation	2.64	2.633	-0.007

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.634	2.637	2.64	0.0042426	2.628	2.6305	2.633	0.0035355	-0.007	-0.0065	-0.006	0.00070711
50	2.628	2.6431	2.657	0.010542	2.554	2.5821	2.606	0.018361	-0.074	-0.061	-0.05	0.010033
100	2.632	2.6467	2.669	0.014638	2.542	2.5608	2.583	0.015955	-0.09	-0.085833	-0.078	0.004916

Device Test: 6.66 VOL_RESET_2MA(VOL_2mA_RESETB2/RESETB2/1.6/3/0/0/2/@VOL_RESET_2MA)





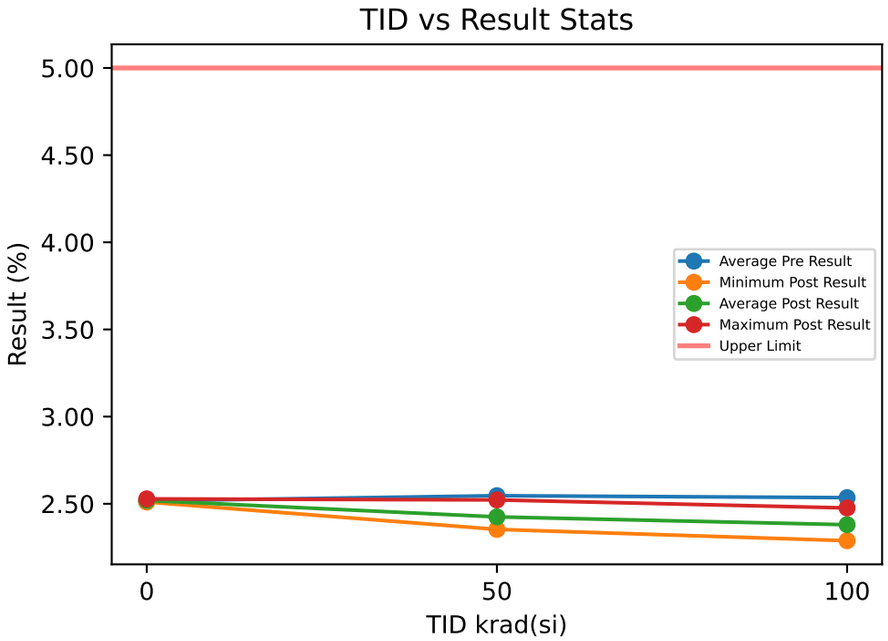
Test Results (Upper Limit = 5.0 (%))

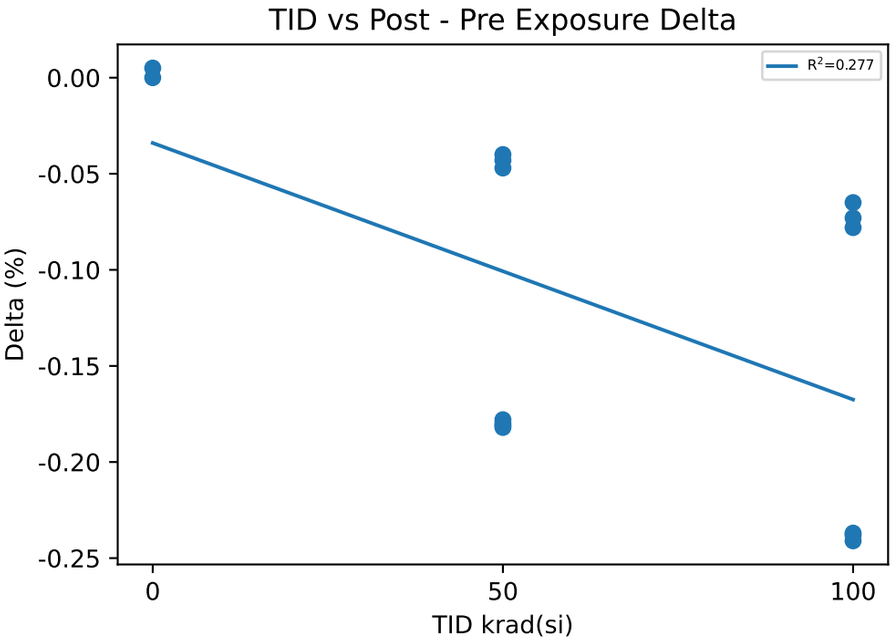
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.564	2.382	-0.182
89	50	Biased	2.571	2.395	-0.176
90	50	Biased	2.569	2.391	-0.178
92	50	Biased	2.6	2.423	-0.177
93	50	Unbiased	2.569	2.528	-0.041
94	50	Unbiased	2.593	2.55	-0.043
95	50	Unbiased	2.56	2.518	-0.042
96	100	Biased	2.57	2.332	-0.238
97	100	Biased	2.573	2.33	-0.243
98	100	Biased	2.562	2.322	-0.24
99	100	Unbiased	2.577	2.502	-0.075
100	100	Unbiased	2.574	2.5	-0.074
101	100	Unbiased	2.558	2.49	-0.068
102	0	Correlation	2.552	2.553	0.001
103	0	Correlation	2.568	2.568	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.552	2.56	2.568	0.011314	2.553	2.5605	2.568	0.010607	0	0.0005	0.001	0.00070711
50	2.56	2.5751	2.6	0.015181	2.382	2.4553	2.55	0.073452	-0.182	-0.11986	-0.041	0.072855
100	2.558	2.569	2.577	0.0074297	2.322	2.4127	2.502	0.092897	-0.243	-0.15633	-0.068	0.092062

Device Test: 6.67 VOL_RESET_2MA(VOL_2mA_RESETB3/RESETB3/1.6/3/0/0/2/@VOL_RESET_2MA)





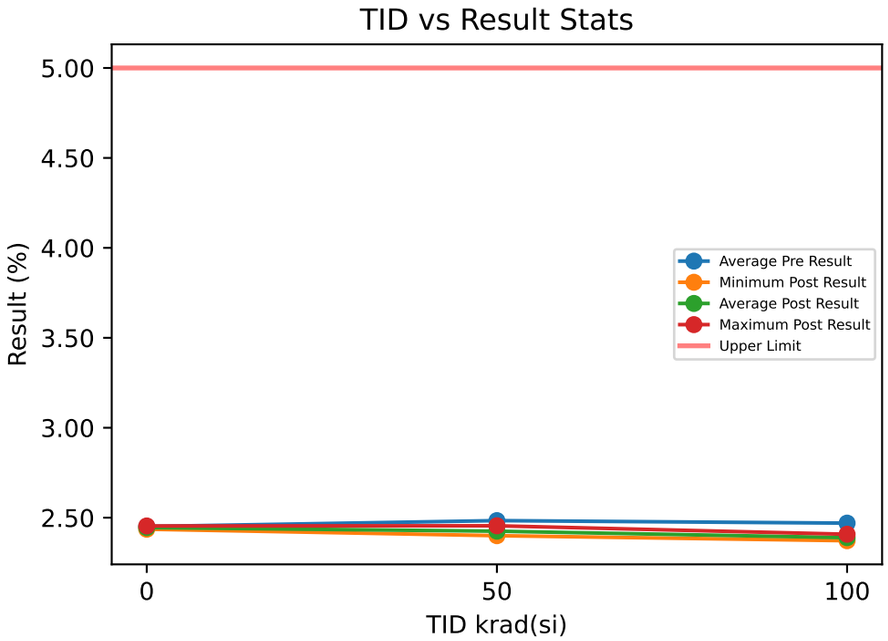
Test Results (Upper Limit = 5.0 (%))

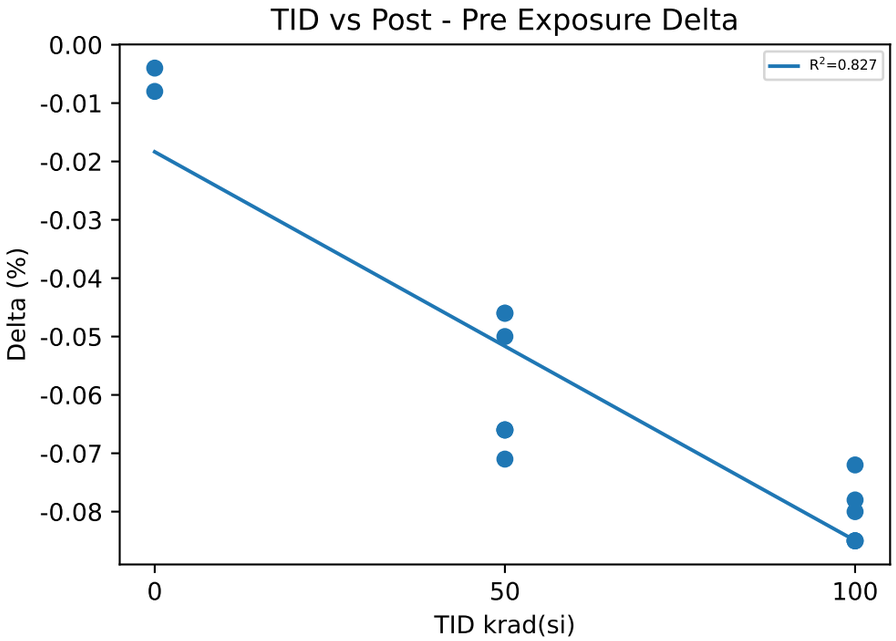
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.531	2.353	-0.178
89	50	Biased	2.549	2.368	-0.181
90	50	Biased	2.544	2.364	-0.18
92	50	Biased	2.572	2.39	-0.182
93	50	Unbiased	2.537	2.494	-0.043
94	50	Unbiased	2.569	2.522	-0.047
95	50	Unbiased	2.522	2.482	-0.04
96	100	Biased	2.544	2.306	-0.238
97	100	Biased	2.531	2.294	-0.237
98	100	Biased	2.529	2.288	-0.241
99	100	Unbiased	2.554	2.476	-0.078
100	100	Unbiased	2.529	2.456	-0.073
101	100	Unbiased	2.524	2.459	-0.065
102	0	Correlation	2.505	2.51	0.005
103	0	Correlation	2.528	2.528	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.505	2.5165	2.528	0.016263	2.51	2.519	2.528	0.012728	0	0.0025	0.005	0.0035355
50	2.522	2.5463	2.572	0.018706	2.353	2.4247	2.522	0.071644	-0.182	-0.12157	-0.04	0.073223
100	2.524	2.5352	2.554	0.011409	2.288	2.3798	2.476	0.09227	-0.241	-0.15533	-0.065	0.091391

Device Test: 6.68 VOL_RESET_2MA(VOL_2mA_RESETB4/RESETB4/1.6/3/0/0/2/@VOL_RESET_2MA)





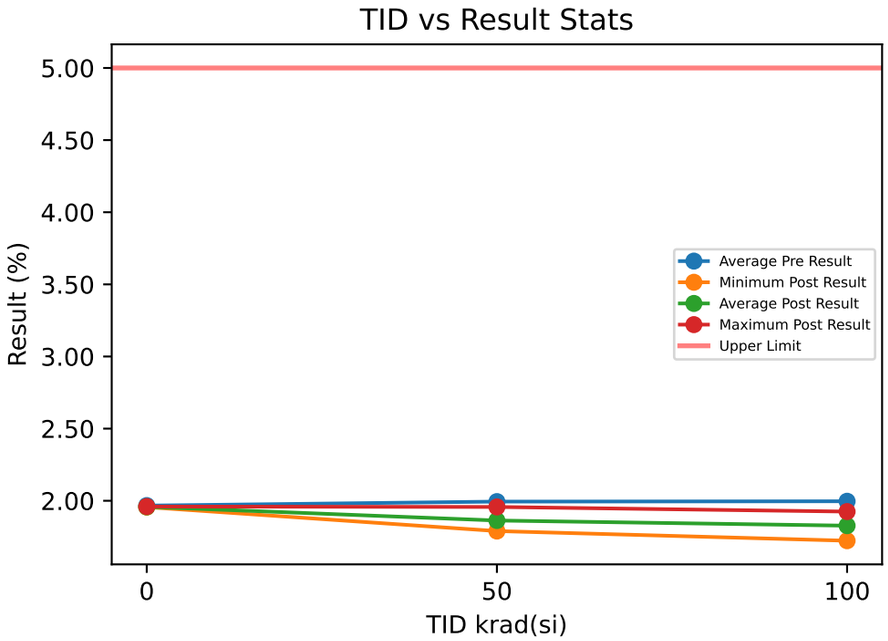
Test Results (Upper Limit = 5.0 (%))

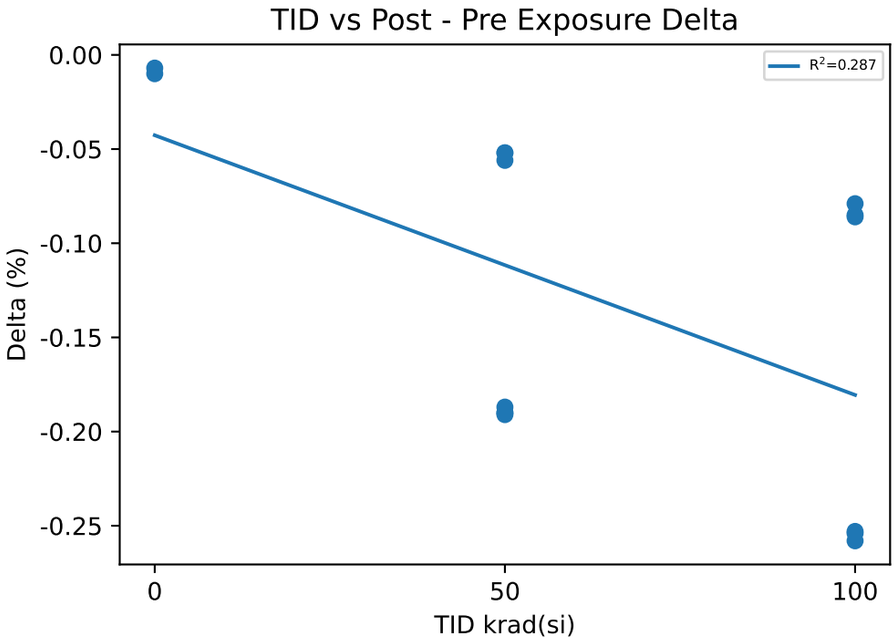
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.471	2.4	-0.071
89	50	Biased	2.478	2.412	-0.066
90	50	Biased	2.482	2.416	-0.066
92	50	Biased	2.521	2.455	-0.066
93	50	Unbiased	2.473	2.427	-0.046
94	50	Unbiased	2.502	2.452	-0.05
95	50	Unbiased	2.459	2.413	-0.046
96	100	Biased	2.486	2.401	-0.085
97	100	Biased	2.468	2.383	-0.085
98	100	Biased	2.457	2.372	-0.085
99	100	Unbiased	2.486	2.408	-0.078
100	100	Unbiased	2.464	2.384	-0.08
101	100	Unbiased	2.458	2.386	-0.072
102	0	Correlation	2.44	2.436	-0.004
103	0	Correlation	2.462	2.454	-0.008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.44	2.451	2.462	0.015556	2.436	2.445	2.454	0.012728	-0.008	-0.006	-0.004	0.0028284
50	2.459	2.4837	2.521	0.021006	2.4	2.425	2.455	0.021024	-0.071	-0.058714	-0.046	0.010874
100	2.457	2.4698	2.486	0.013152	2.372	2.389	2.408	0.013145	-0.085	-0.080833	-0.072	0.0052694

Device Test: 6.69 VOL_WDO_2MA(VOL_2mA_WDOB/WDOB/1.6/3/0/0/2/@VOL_WDO_2MA)





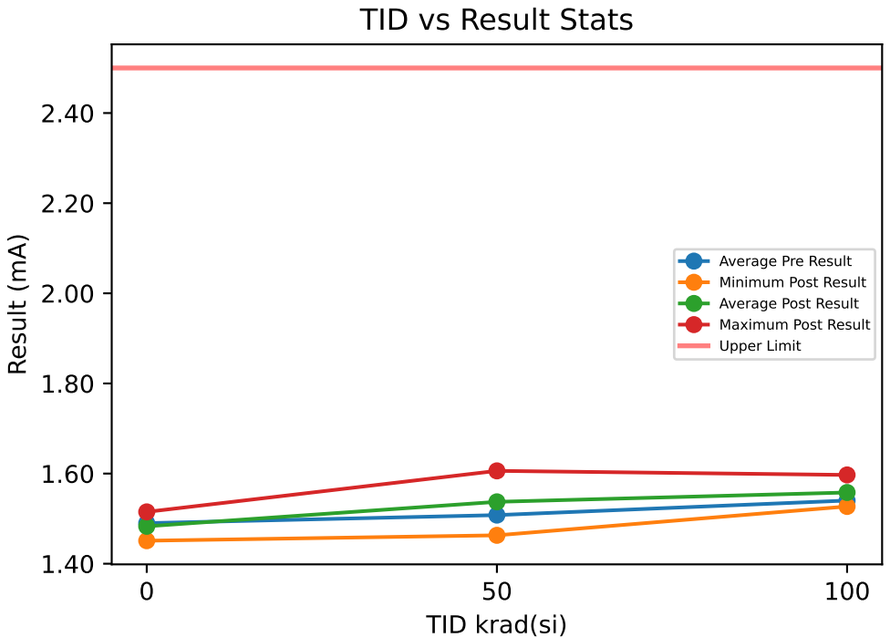
Test Results (Upper Limit = 5.0 (%))

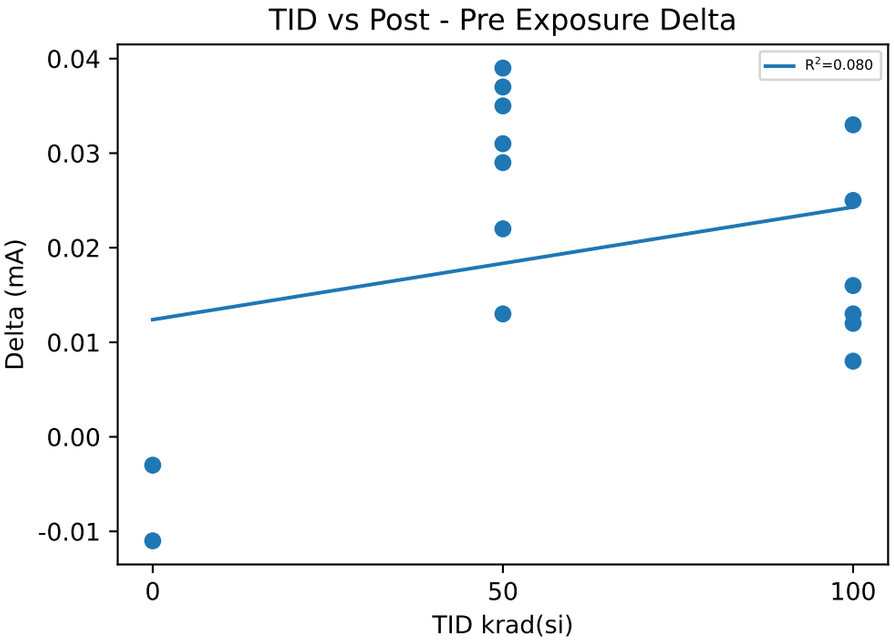
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.98	1.79	-0.19
89	50	Biased	1.992	1.801	-0.191
90	50	Biased	1.995	1.808	-0.187
92	50	Biased	2.004	1.814	-0.19
93	50	Unbiased	1.987	1.935	-0.052
94	50	Unbiased	2.013	1.957	-0.056
95	50	Unbiased	1.988	1.936	-0.052
96	100	Biased	2.017	1.759	-0.258
97	100	Biased	1.986	1.733	-0.253
98	100	Biased	1.977	1.723	-0.254
99	100	Unbiased	2.011	1.925	-0.086
100	100	Unbiased	1.997	1.912	-0.085
101	100	Unbiased	1.991	1.912	-0.079
102	0	Correlation	1.963	1.956	-0.007
103	0	Correlation	1.97	1.96	-0.01

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.963	1.9665	1.97	0.0049497	1.956	1.958	1.96	0.0028284	-0.01	-0.0085	-0.007	0.0021213
50	1.98	1.9941	2.013	0.011157	1.79	1.863	1.957	0.07522	-0.191	-0.13114	-0.052	0.072807
100	1.977	1.9965	2.017	0.015176	1.723	1.8273	1.925	0.098315	-0.258	-0.16917	-0.079	0.094071

Device Test: 6.7 IQ(IQ3_High/IN//14/0/0/0/@IQ)





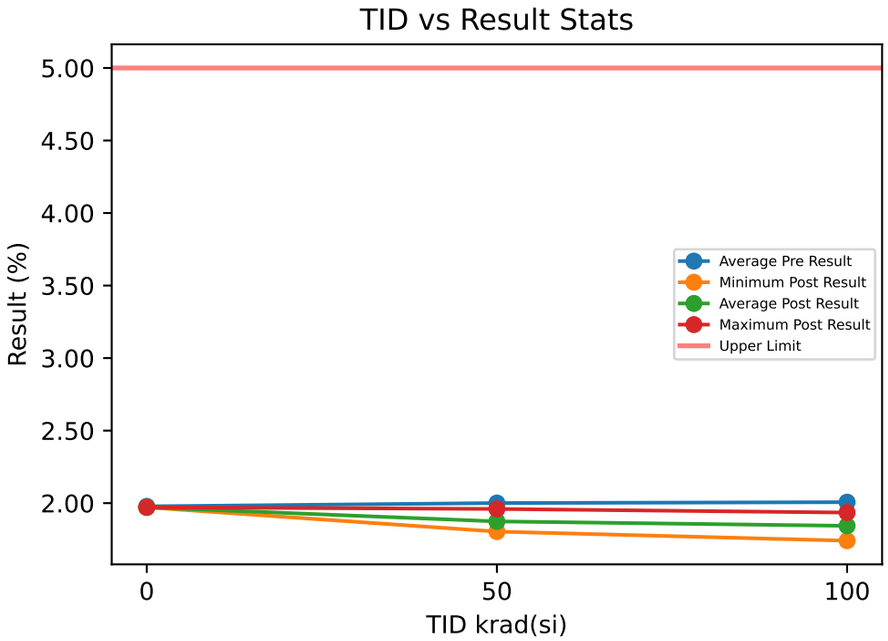
Test Results (Upper Limit = 2.5 (mA))

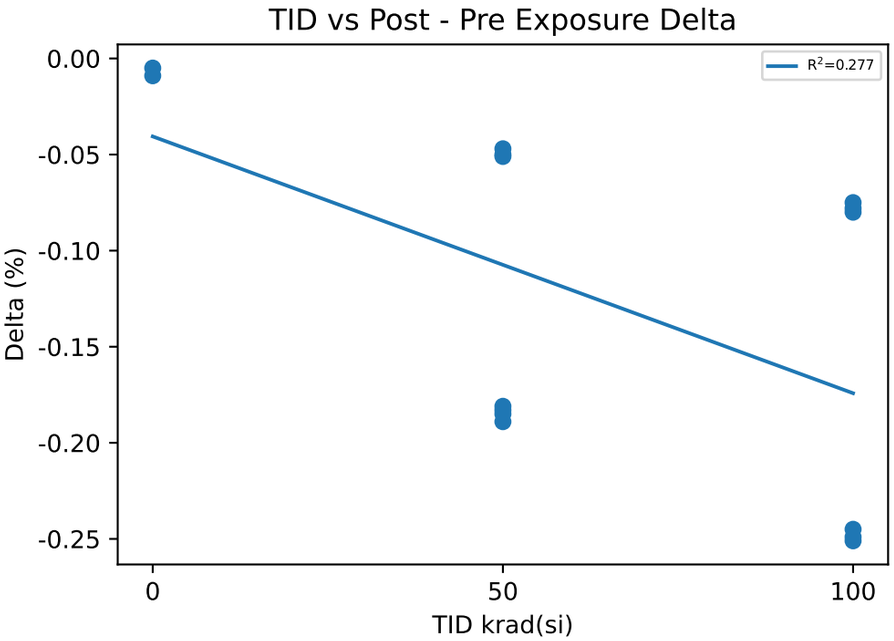
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.494	1.531	0.037
89	50	Biased	1.554	1.585	0.031
90	50	Biased	1.567	1.606	0.039
92	50	Biased	1.522	1.535	0.013
93	50	Unbiased	1.482	1.504	0.022
94	50	Unbiased	1.502	1.537	0.035
95	50	Unbiased	1.434	1.463	0.029
96	100	Biased	1.585	1.597	0.012
97	100	Biased	1.494	1.527	0.033
98	100	Biased	1.547	1.555	0.008
99	100	Unbiased	1.552	1.568	0.016
100	100	Unbiased	1.527	1.54	0.013
101	100	Unbiased	1.536	1.561	0.025
102	0	Correlation	1.518	1.515	-0.003
103	0	Correlation	1.462	1.451	-0.011

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.462	1.49	1.518	0.039598	1.451	1.483	1.515	0.045255	-0.011	-0.007	-0.003	0.0056569
50	1.434	1.5079	1.567	0.04505	1.463	1.5373	1.606	0.047731	0.013	0.029429	0.039	0.0091989
100	1.494	1.5402	1.585	0.030063	1.527	1.558	1.597	0.024183	0.008	0.017833	0.033	0.0093684

Device Test: 6.70 VOL_PWRGD_2MA(VOL_2mA_PWRGD/PWRGD/1.6/3/0/0/2/@VOL_PWRGD_2MA)





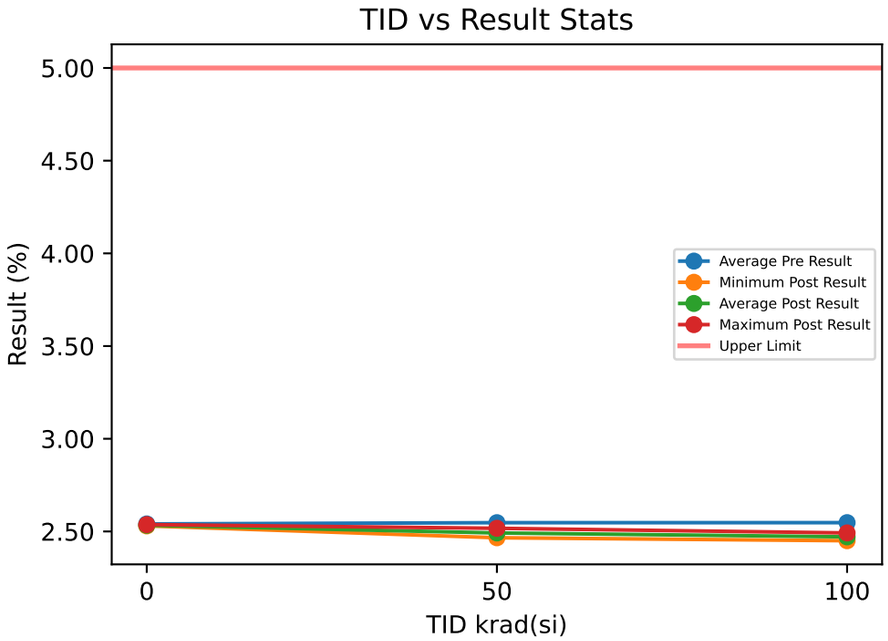
Test Results (Upper Limit = 5.0 (%))

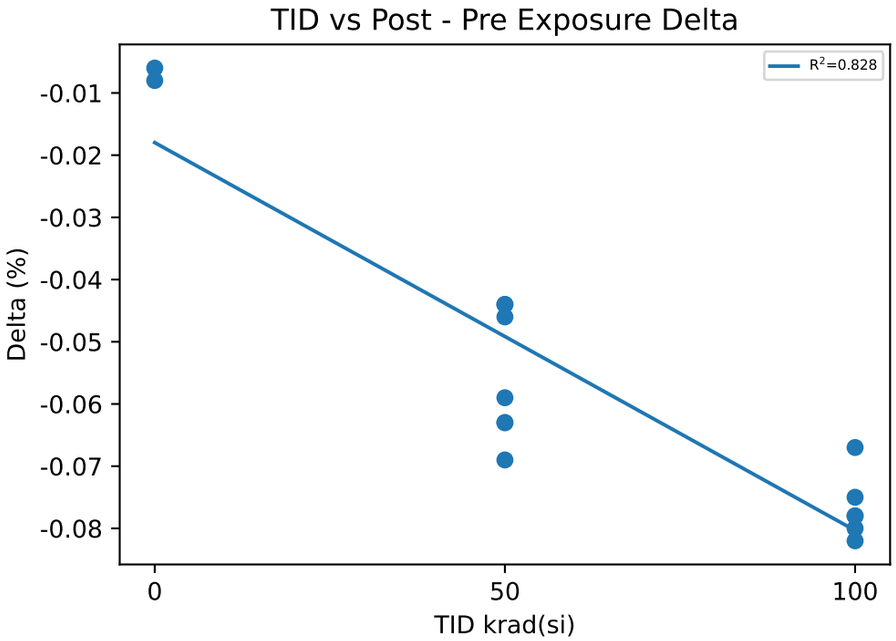
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.989	1.804	-0.185
89	50	Biased	1.997	1.808	-0.189
90	50	Biased	1.999	1.816	-0.183
92	50	Biased	2.016	1.835	-0.181
93	50	Unbiased	1.998	1.947	-0.051
94	50	Unbiased	2.01	1.96	-0.05
95	50	Unbiased	1.996	1.949	-0.047
96	100	Biased	2.025	1.774	-0.251
97	100	Biased	1.995	1.75	-0.245
98	100	Biased	1.99	1.741	-0.249
99	100	Unbiased	2.013	1.935	-0.078
100	100	Unbiased	2.015	1.935	-0.08
101	100	Unbiased	2.002	1.927	-0.075
102	0	Correlation	1.976	1.971	-0.005
103	0	Correlation	1.98	1.971	-0.009

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.976	1.978	1.98	0.0028284	1.971	1.971	1.971	0	-0.009	-0.007	-0.005	0.0028284
50	1.989	2.0007	2.016	0.00916	1.804	1.8741	1.96	0.073588	-0.189	-0.12657	-0.047	0.0723
100	1.99	2.0067	2.025	0.013277	1.741	1.8437	1.935	0.09777	-0.251	-0.163	-0.075	0.093511

Device Test: 6.71 VOL_RESET_2MA(VOL_2mA_RESETB1/RESETB1/1.6/14/0/0/2/@VOL_RESET_2MA)





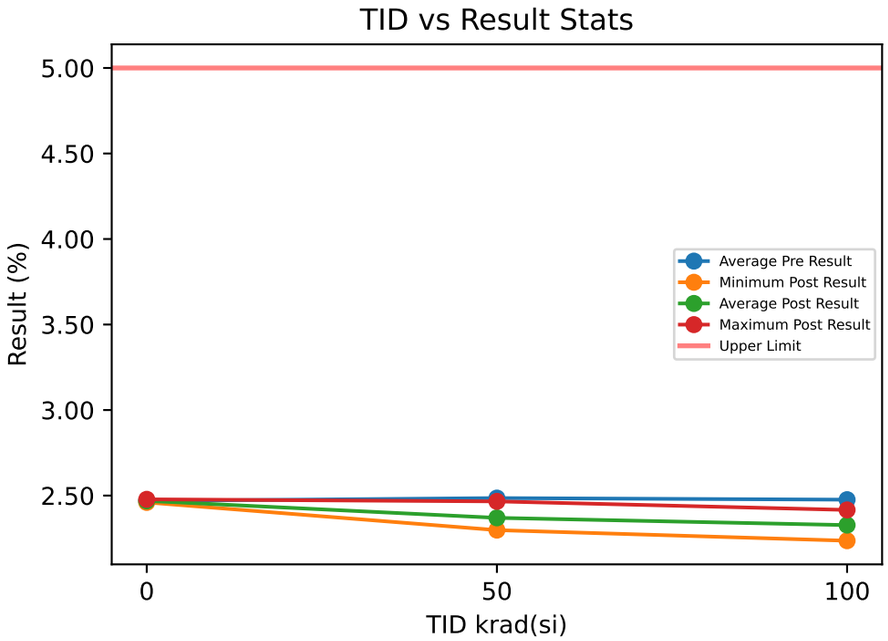
Test Results (Upper Limit = 5.0 (%))

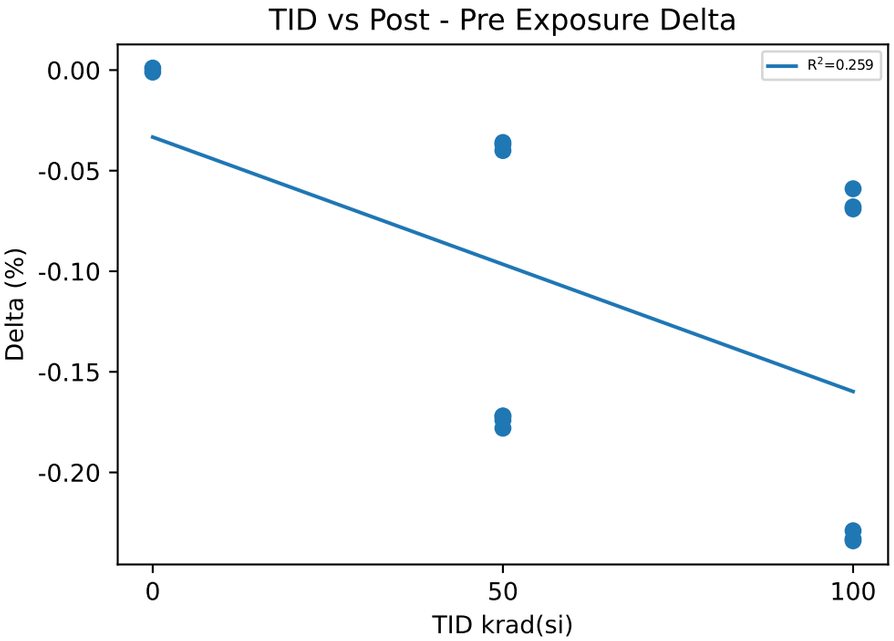
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.535	2.466	-0.069
89	50	Biased	2.548	2.485	-0.063
90	50	Biased	2.558	2.495	-0.063
92	50	Biased	2.533	2.474	-0.059
93	50	Unbiased	2.548	2.504	-0.044
94	50	Unbiased	2.563	2.517	-0.046
95	50	Unbiased	2.546	2.502	-0.044
96	100	Biased	2.559	2.481	-0.078
97	100	Biased	2.533	2.453	-0.08
98	100	Biased	2.532	2.45	-0.082
99	100	Unbiased	2.57	2.492	-0.078
100	100	Unbiased	2.544	2.469	-0.075
101	100	Unbiased	2.547	2.48	-0.067
102	0	Correlation	2.536	2.53	-0.006
103	0	Correlation	2.545	2.537	-0.008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.536	2.5405	2.545	0.006364	2.53	2.5335	2.537	0.0049497	-0.008	-0.007	-0.006	0.0014142
50	2.533	2.5473	2.563	0.01095	2.466	2.4919	2.517	0.01792	-0.069	-0.055429	-0.044	0.010502
100	2.532	2.5475	2.57	0.014843	2.45	2.4708	2.492	0.016678	-0.082	-0.076667	-0.067	0.0052789

Device Test: 6.72 VOL_RESET_2MA(VOL_2mA_RESETB2/RESETB2/1.6/14/0/0/2/@VOL_RESET_2MA)





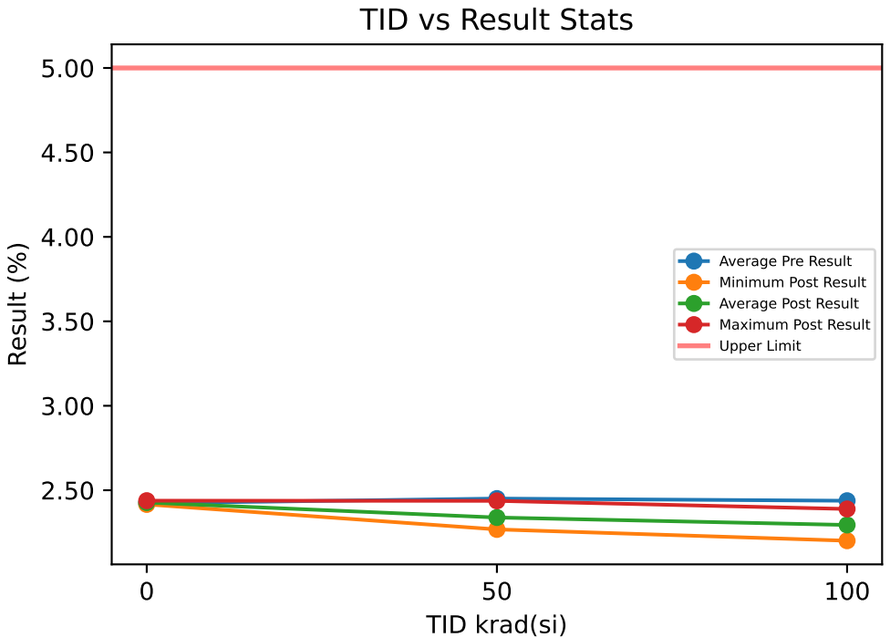
Test Results (Upper Limit = 5.0 (%))

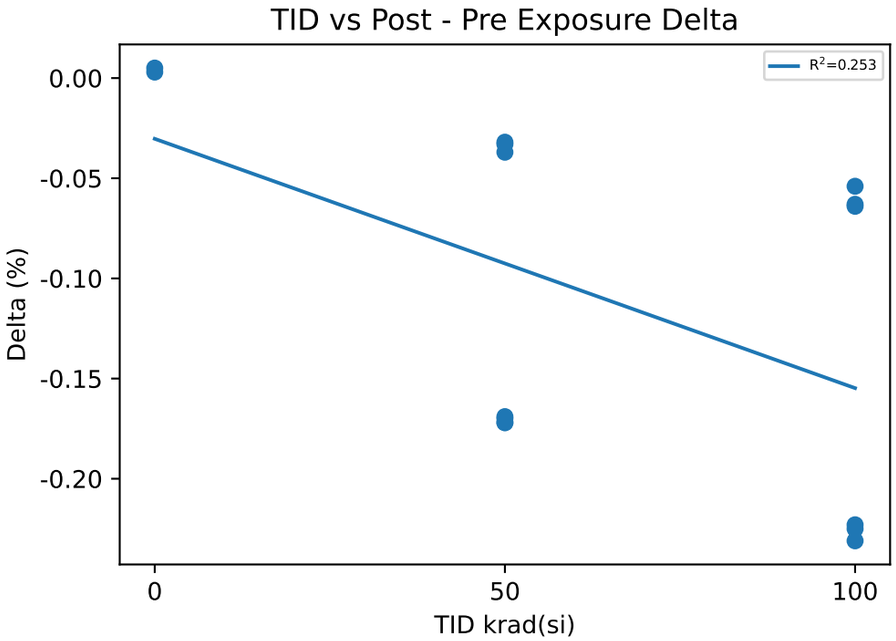
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.476	2.298	-0.178
89	50	Biased	2.483	2.311	-0.172
90	50	Biased	2.483	2.309	-0.174
92	50	Biased	2.509	2.337	-0.172
93	50	Unbiased	2.472	2.436	-0.036
94	50	Unbiased	2.506	2.466	-0.04
95	50	Unbiased	2.468	2.431	-0.037
96	100	Biased	2.478	2.249	-0.229
97	100	Biased	2.477	2.243	-0.234
98	100	Biased	2.469	2.236	-0.233
99	100	Unbiased	2.485	2.416	-0.069
100	100	Unbiased	2.482	2.414	-0.068
101	100	Unbiased	2.465	2.406	-0.059
102	0	Correlation	2.459	2.46	0.001
103	0	Correlation	2.479	2.478	-0.001

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.459	2.469	2.479	0.014142	2.46	2.469	2.478	0.012728	-0.001	0	0.001	0.0014142
50	2.468	2.4853	2.509	0.016142	2.298	2.3697	2.466	0.071609	-0.178	-0.11557	-0.036	0.072911
100	2.465	2.476	2.485	0.007642	2.236	2.3273	2.416	0.092899	-0.234	-0.14867	-0.059	0.091369

Device Test: 6.73 VOL_RESET_2MA(VOL_2mA_RESETB3/RESETB3/1.6/14/0/0/2/@VOL_RESET_2MA)





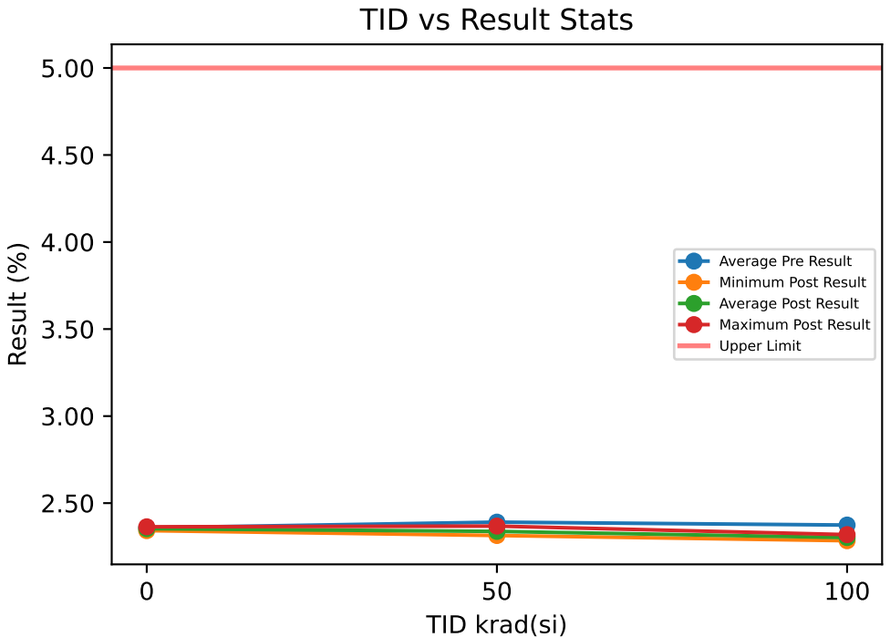
Test Results (Upper Limit = 5.0 (%))

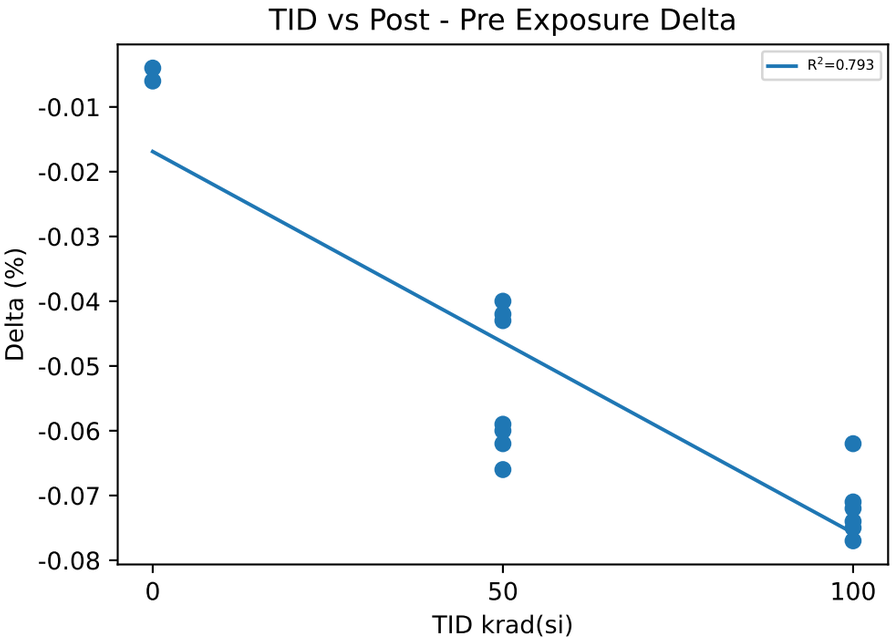
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.44	2.268	-0.172
89	50	Biased	2.453	2.283	-0.17
90	50	Biased	2.45	2.281	-0.169
92	50	Biased	2.474	2.302	-0.172
93	50	Unbiased	2.436	2.403	-0.033
94	50	Unbiased	2.474	2.437	-0.037
95	50	Unbiased	2.427	2.395	-0.032
96	100	Biased	2.446	2.223	-0.223
97	100	Biased	2.432	2.207	-0.225
98	100	Biased	2.432	2.201	-0.231
99	100	Unbiased	2.453	2.389	-0.064
100	100	Unbiased	2.434	2.371	-0.063
101	100	Unbiased	2.429	2.375	-0.054
102	0	Correlation	2.411	2.416	0.005
103	0	Correlation	2.435	2.438	0.003

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.411	2.423	2.435	0.016971	2.416	2.427	2.438	0.015556	0.003	0.004	0.005	0.0014142
50	2.427	2.4506	2.474	0.018183	2.268	2.3384	2.437	0.070408	-0.172	-0.11214	-0.032	0.07312
100	2.429	2.4377	2.453	0.0095638	2.201	2.2943	2.389	0.092491	-0.231	-0.14333	-0.054	0.091027

Device Test: 6.74 VOL_RESET_2MA(VOL_2mA_RESETB4/RESETB4/1.6/14/0/0/2/@VOL_RESET_2MA)





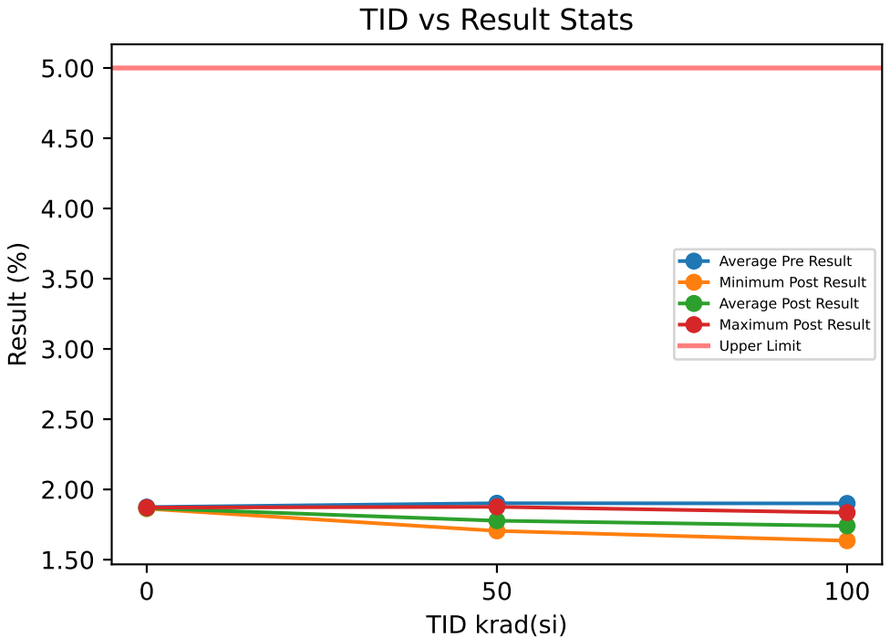
Test Results (Upper Limit = 5.0 (%))

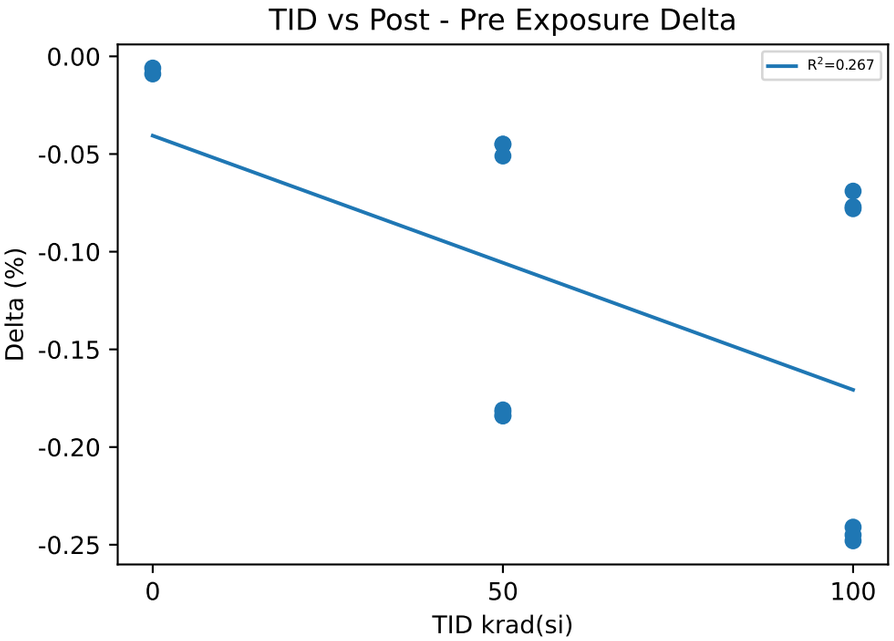
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	2.38	2.314	-0.066
89	50	Biased	2.387	2.325	-0.062
90	50	Biased	2.391	2.332	-0.059
92	50	Biased	2.426	2.366	-0.06
93	50	Unbiased	2.375	2.333	-0.042
94	50	Unbiased	2.411	2.368	-0.043
95	50	Unbiased	2.365	2.325	-0.04
96	100	Biased	2.39	2.316	-0.074
97	100	Biased	2.37	2.295	-0.075
98	100	Biased	2.361	2.284	-0.077
99	100	Unbiased	2.39	2.319	-0.071
100	100	Unbiased	2.37	2.298	-0.072
101	100	Unbiased	2.363	2.301	-0.062
102	0	Correlation	2.346	2.342	-0.004
103	0	Correlation	2.37	2.364	-0.006

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.346	2.358	2.37	0.016971	2.342	2.353	2.364	0.015556	-0.006	-0.005	-0.004	0.0014142
50	2.365	2.3907	2.426	0.021187	2.314	2.3376	2.368	0.021046	-0.066	-0.053143	-0.04	0.010991
100	2.361	2.374	2.39	0.012915	2.284	2.3022	2.319	0.013227	-0.077	-0.071833	-0.062	0.0052694

Device Test: 6.75 VOL_WDO_2MA(VOL_2mA_WDOB/WDOB/1.6/14/0/0/2/@VOL_WDO_2MA)





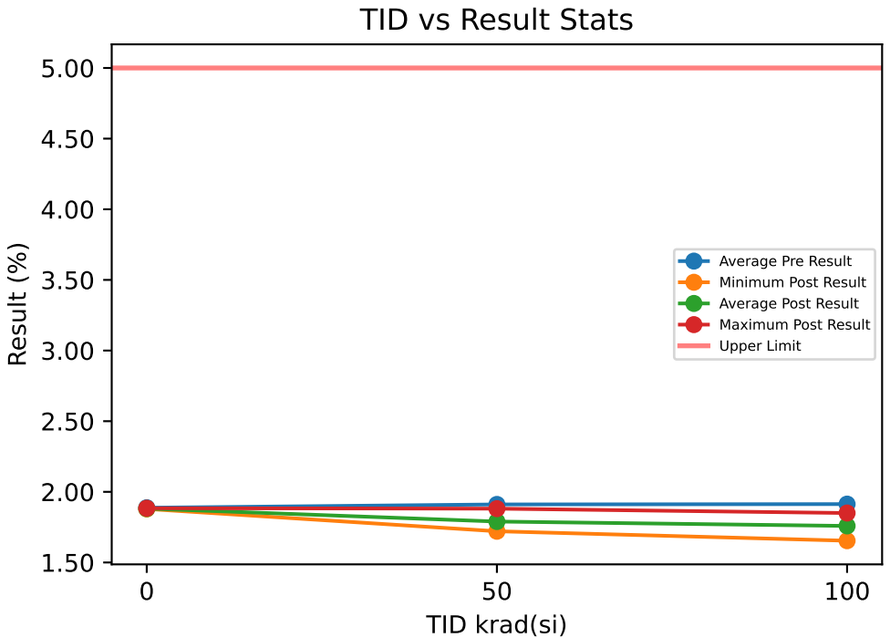
Test Results (Upper Limit = 5.0 (%))

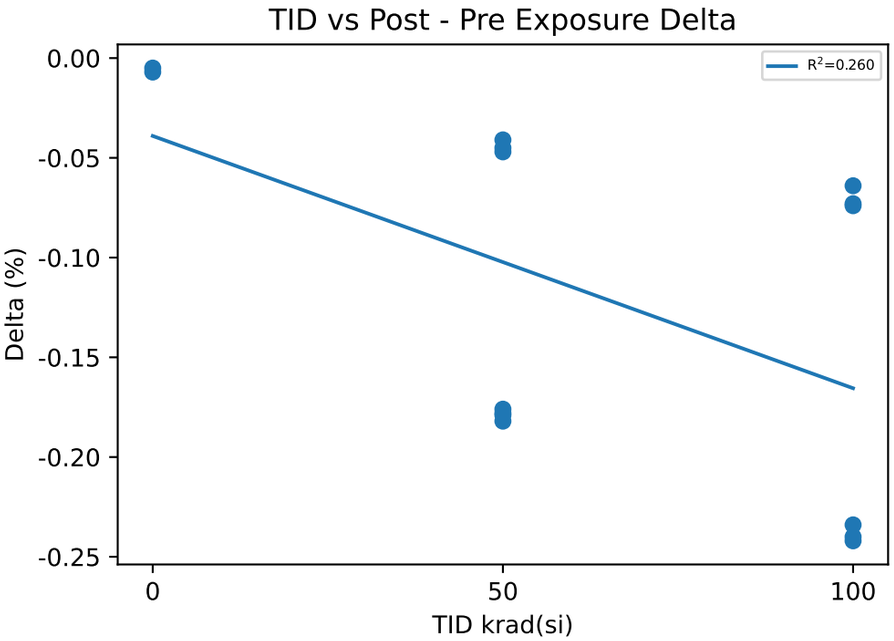
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.889	1.705	-0.184
89	50	Biased	1.9	1.716	-0.184
90	50	Biased	1.904	1.723	-0.181
92	50	Biased	1.91	1.728	-0.182
93	50	Unbiased	1.89	1.845	-0.045
94	50	Unbiased	1.927	1.876	-0.051
95	50	Unbiased	1.893	1.848	-0.045
96	100	Biased	1.922	1.674	-0.248
97	100	Biased	1.889	1.648	-0.241
98	100	Biased	1.88	1.635	-0.245
99	100	Unbiased	1.913	1.835	-0.078
100	100	Unbiased	1.904	1.827	-0.077
101	100	Unbiased	1.895	1.826	-0.069
102	0	Correlation	1.869	1.863	-0.006
103	0	Correlation	1.88	1.871	-0.009

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.869	1.8745	1.88	0.0077782	1.863	1.867	1.871	0.0056569	-0.009	-0.0075	-0.006	0.0021213
50	1.889	1.9019	1.927	0.013484	1.705	1.7773	1.876	0.07493	-0.184	-0.12457	-0.045	0.072597
100	1.88	1.9005	1.922	0.015579	1.635	1.7408	1.835	0.097807	-0.248	-0.15967	-0.069	0.093192

Device Test: 6.76 VOL_PWRGD_2MA(VOL_2mA_PWRGD/PWRGD/1.6/14/0/0/2/@VOL_PWRGD_2MA)





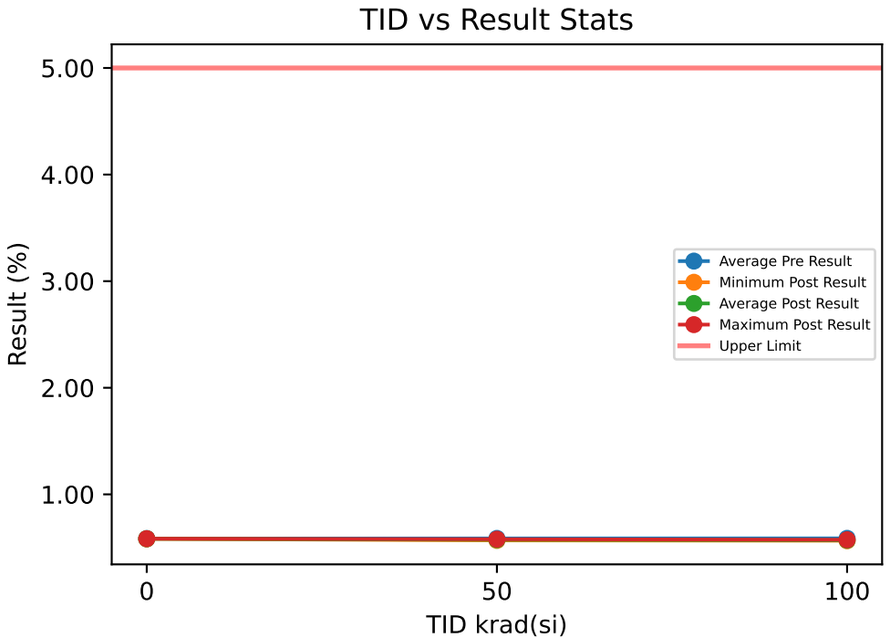
Test Results (Upper Limit = 5.0 (%))

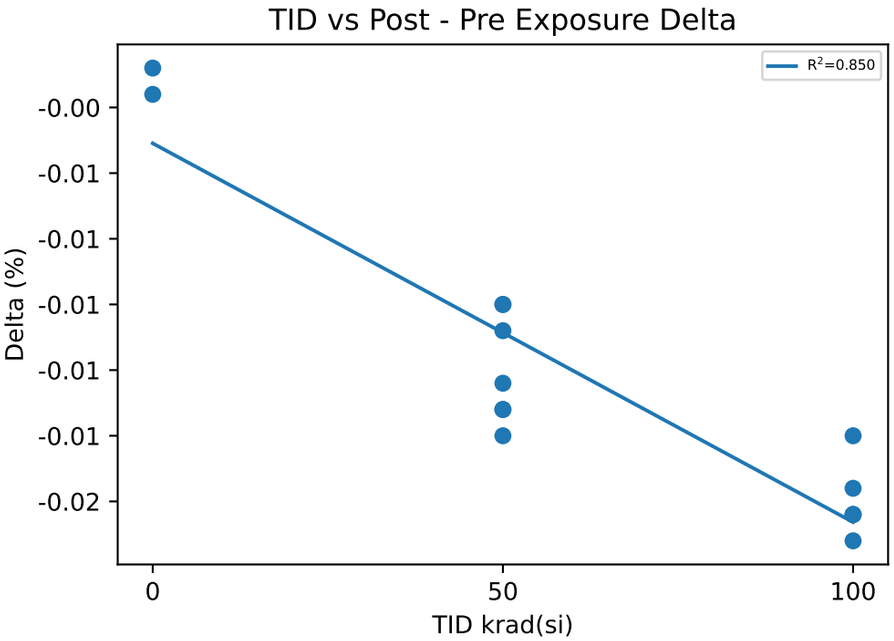
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	1.9	1.721	-0.179
89	50	Biased	1.906	1.724	-0.182
90	50	Biased	1.909	1.733	-0.176
92	50	Biased	1.927	1.749	-0.178
93	50	Unbiased	1.903	1.858	-0.045
94	50	Unbiased	1.928	1.881	-0.047
95	50	Unbiased	1.903	1.862	-0.041
96	100	Biased	1.933	1.691	-0.242
97	100	Biased	1.9	1.666	-0.234
98	100	Biased	1.894	1.654	-0.24
99	100	Unbiased	1.921	1.848	-0.073
100	100	Unbiased	1.924	1.85	-0.074
101	100	Unbiased	1.907	1.843	-0.064
102	0	Correlation	1.884	1.879	-0.005
103	0	Correlation	1.891	1.884	-0.007

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.884	1.8875	1.891	0.0049497	1.879	1.8815	1.884	0.0035355	-0.007	-0.006	-0.005	0.0014142
50	1.9	1.9109	1.928	0.011711	1.721	1.7897	1.881	0.073184	-0.182	-0.12114	-0.041	0.071892
100	1.894	1.9132	1.933	0.015171	1.654	1.7587	1.85	0.097525	-0.242	-0.1545	-0.064	0.092303

Device Test: 6.77 VOL_RESET_2MA(VOL_2mA_RESETB1/RESETB1/7/3/0/0/2/@VOL_RESET_2MA)





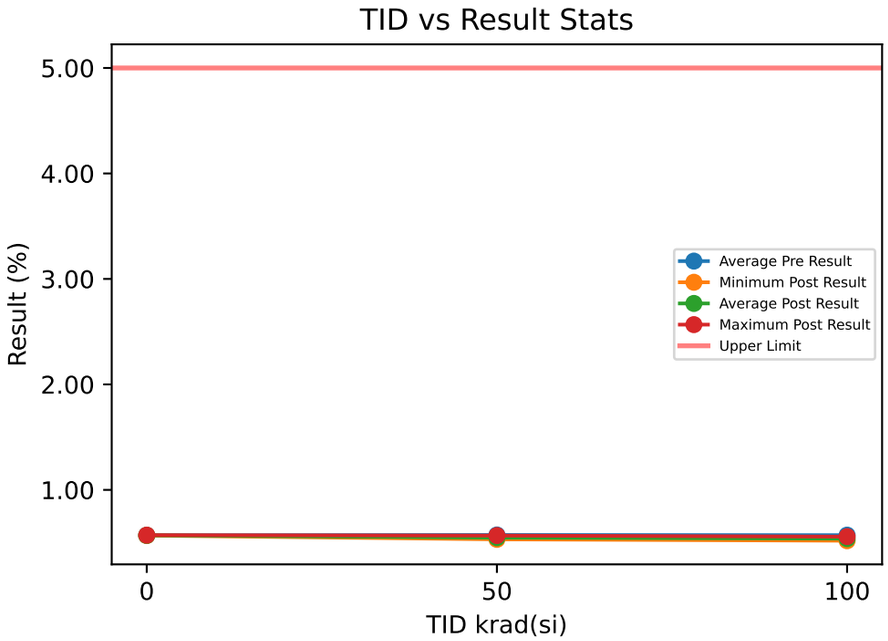
Test Results (Upper Limit = 5.0 (%))

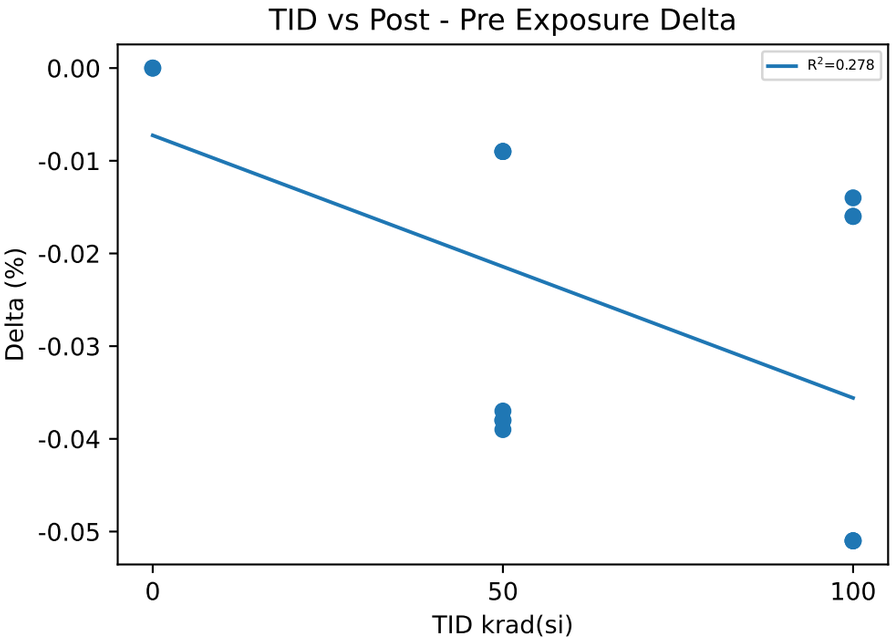
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.583	0.568	-0.015
89	50	Biased	0.587	0.573	-0.014
90	50	Biased	0.588	0.574	-0.014
92	50	Biased	0.584	0.571	-0.013
93	50	Unbiased	0.587	0.577	-0.01
94	50	Unbiased	0.59	0.579	-0.011
95	50	Unbiased	0.586	0.576	-0.01
96	100	Biased	0.59	0.572	-0.018
97	100	Biased	0.584	0.565	-0.019
98	100	Biased	0.584	0.566	-0.018
99	100	Unbiased	0.592	0.574	-0.018
100	100	Unbiased	0.586	0.569	-0.017
101	100	Unbiased	0.586	0.571	-0.015
102	0	Correlation	0.584	0.583	-0.001
103	0	Correlation	0.586	0.584	-0.002

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.584	0.585	0.586	0.0014142	0.583	0.5835	0.584	0.00070711	-0.002	-0.0015	-0.001	0.00070711
50	0.583	0.58643	0.59	0.0023705	0.568	0.574	0.579	0.0037417	-0.015	-0.012429	-0.01	0.0020702
100	0.584	0.587	0.592	0.0032863	0.565	0.5695	0.574	0.0035071	-0.019	-0.0175	-0.015	0.0013784

Device Test: 6.78 VOL_RESET_2MA(VOL_2mA_RESETB2/RESETB2/7/3/0/0/2/@VOL_RESET_2MA)





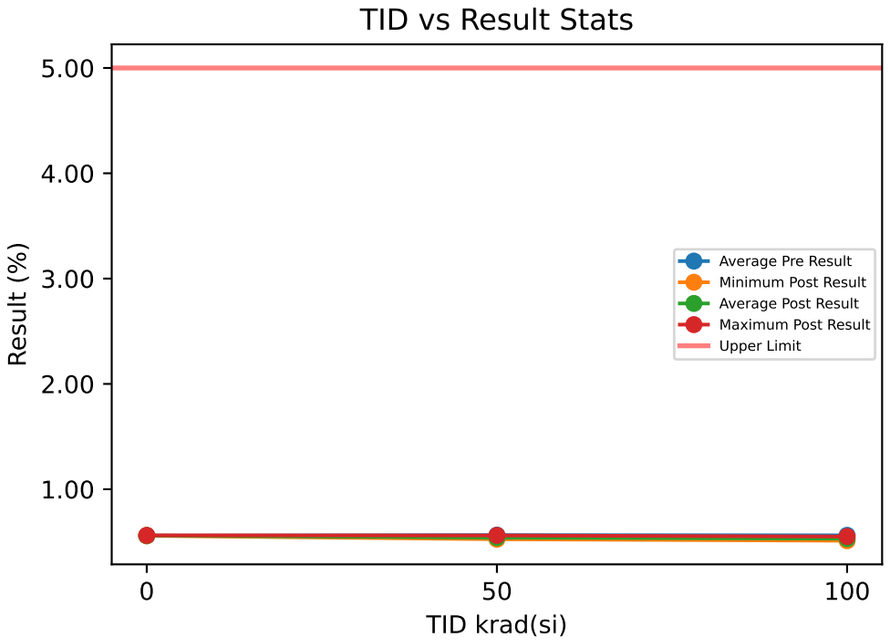
Test Results (Upper Limit = 5.0 (%))

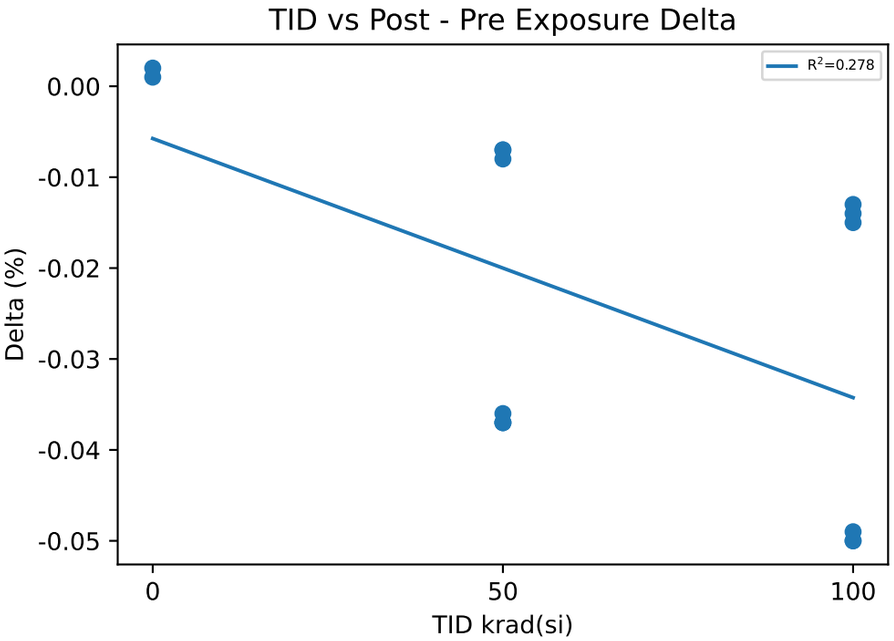
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.57	0.531	-0.039
89	50	Biased	0.572	0.535	-0.037
90	50	Biased	0.571	0.533	-0.038
92	50	Biased	0.578	0.54	-0.038
93	50	Unbiased	0.571	0.562	-0.009
94	50	Unbiased	0.576	0.567	-0.009
95	50	Unbiased	0.569	0.56	-0.009
96	100	Biased	0.572	0.521	-0.051
97	100	Biased	0.571	0.52	-0.051
98	100	Biased	0.569	0.518	-0.051
99	100	Unbiased	0.573	0.557	-0.016
100	100	Unbiased	0.572	0.556	-0.016
101	100	Unbiased	0.568	0.554	-0.014
102	0	Correlation	0.567	0.567	0
103	0	Correlation	0.571	0.571	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.567	0.569	0.571	0.0028284	0.567	0.569	0.571	0.0028284	0	0	0	0
50	0.569	0.57243	0.578	0.0033094	0.531	0.54686	0.567	0.015486	-0.039	-0.025571	-0.009	0.015512
100	0.568	0.57083	0.573	0.0019408	0.518	0.53767	0.557	0.019765	-0.051	-0.033167	-0.014	0.019549

Device Test: 6.79 VOL_RESET_2MA(VOL_2mA_RESETB3/RESETB3/7/3/0/0/2/@VOL_RESET_2MA)





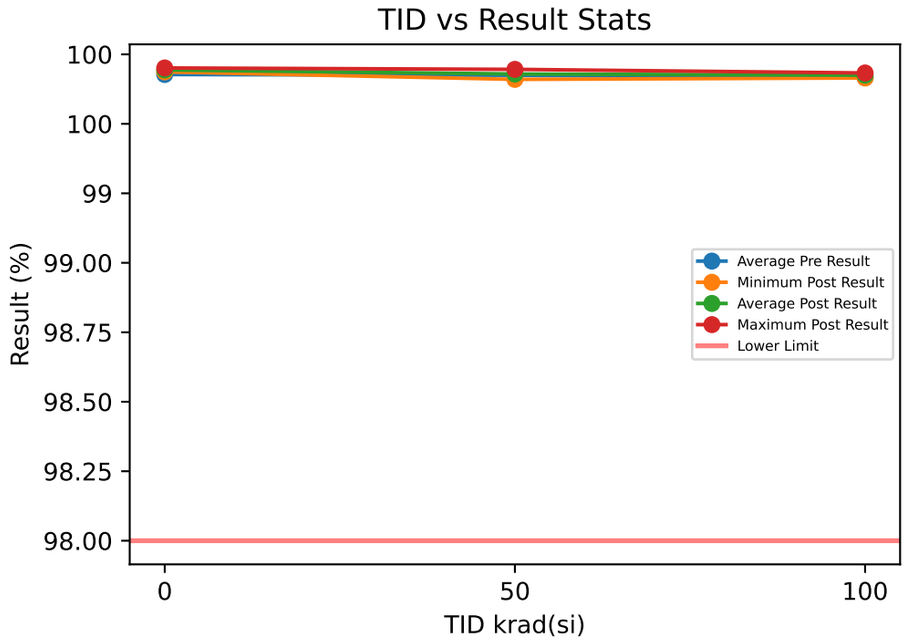
Test Results (Upper Limit = 5.0 (%))

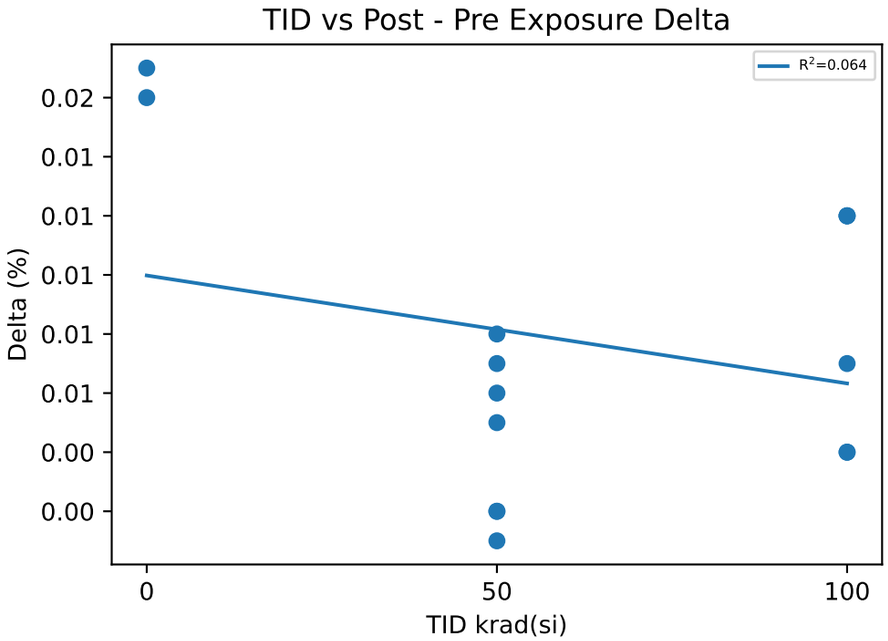
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.562	0.525	-0.037
89	50	Biased	0.565	0.528	-0.037
90	50	Biased	0.563	0.527	-0.036
92	50	Biased	0.57	0.533	-0.037
93	50	Unbiased	0.562	0.555	-0.007
94	50	Unbiased	0.569	0.561	-0.008
95	50	Unbiased	0.559	0.552	-0.007
96	100	Biased	0.564	0.515	-0.049
97	100	Biased	0.561	0.511	-0.05
98	100	Biased	0.561	0.511	-0.05
99	100	Unbiased	0.566	0.551	-0.015
100	100	Unbiased	0.561	0.547	-0.014
101	100	Unbiased	0.56	0.547	-0.013
102	0	Correlation	0.556	0.558	0.002
103	0	Correlation	0.561	0.562	0.001

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.556	0.5585	0.561	0.0035355	0.558	0.56	0.562	0.0028284	0.001	0.0015	0.002	0.00070711
50	0.559	0.56429	0.57	0.0039881	0.525	0.54014	0.561	0.015258	-0.037	-0.024143	-0.007	0.015731
100	0.56	0.56217	0.566	0.0023166	0.511	0.53033	0.551	0.019826	-0.05	-0.031833	-0.013	0.019549

Device Test: 6.8 VLDO_DO(VLDO_pcnt/VLDO//3/0/0/0/@VLDO_DO)





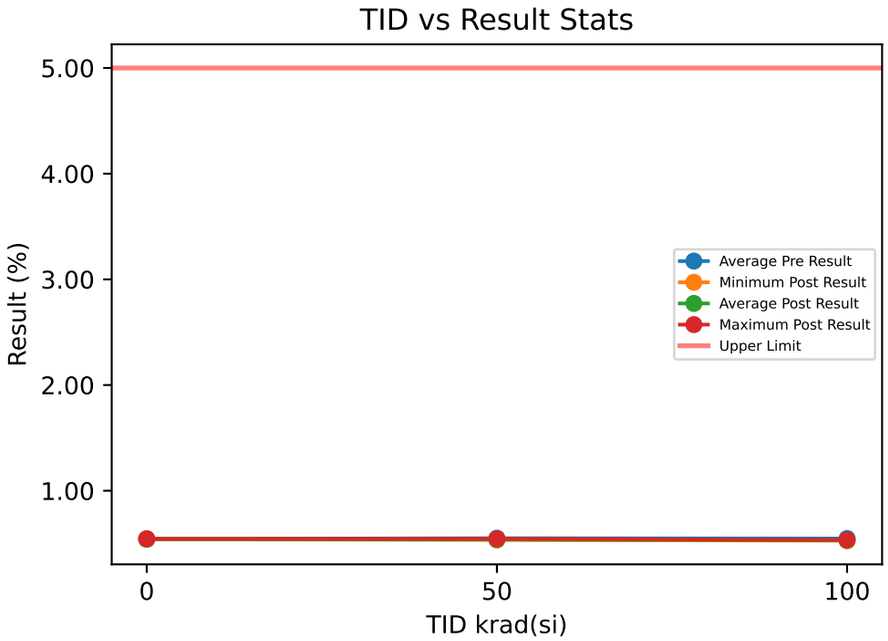
Test Results (Lower Limit = 98.0 (%))

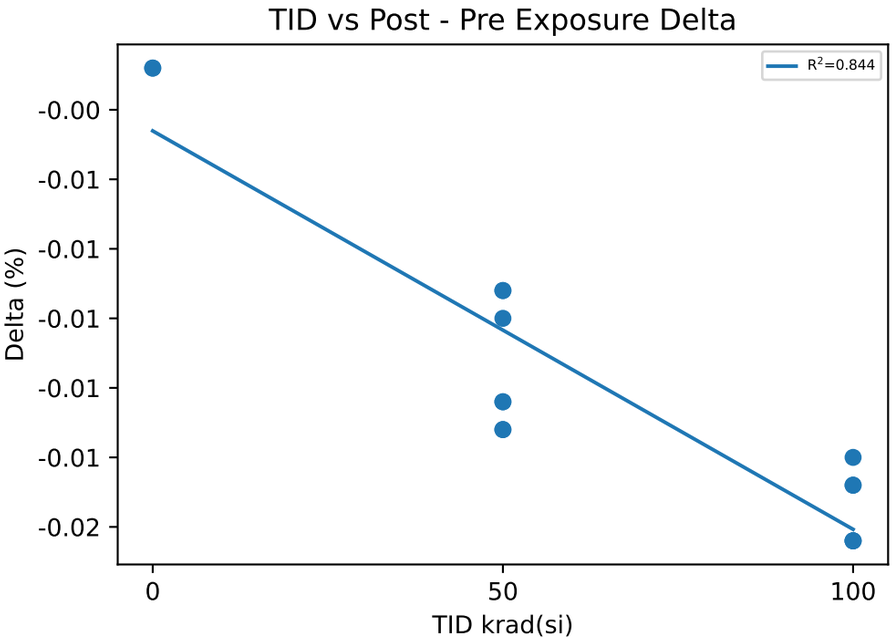
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	99.676	99.678	0.002
89	50	Biased	99.666	99.672	0.006
90	50	Biased	99.659	99.66	0.001
92	50	Biased	99.674	99.681	0.007
93	50	Unbiased	99.681	99.689	0.008
94	50	Unbiased	99.677	99.679	0.002
95	50	Unbiased	99.691	99.696	0.005
96	100	Biased	99.653	99.665	0.012
97	100	Biased	99.679	99.683	0.004
98	100	Biased	99.669	99.681	0.012
99	100	Unbiased	99.665	99.672	0.007
100	100	Unbiased	99.668	99.68	0.012
101	100	Unbiased	99.665	99.669	0.004
102	0	Correlation	99.67	99.687	0.017
103	0	Correlation	99.685	99.701	0.016

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.67	99.678	99.685	0.010607	99.687	99.694	99.701	0.0098995	0.016	0.0165	0.017	0.00070711
50	99.659	99.675	99.691	0.010286	99.66	99.679	99.696	0.011572	0.001	0.0044286	0.008	0.0027603
100	99.653	99.666	99.679	0.0083845	99.665	99.675	99.683	0.0073485	0.004	0.0085	0.012	0.0039875

Device Test: 6.80 VOL_RESET_2MA(VOL_2mA_RESETB4/RESETB4/7/3/0/0/2/@VOL_RESET_2MA)





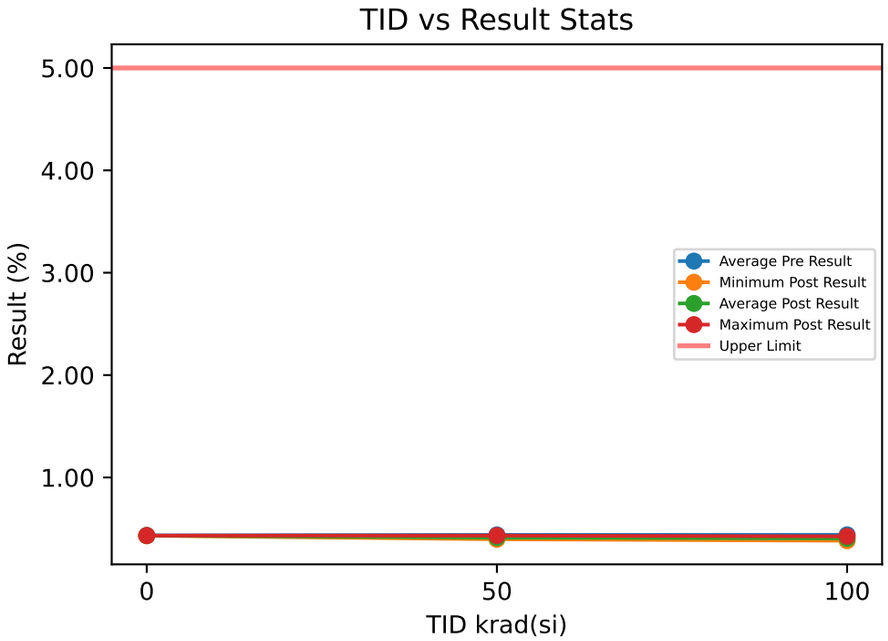
Test Results (Upper Limit = 5.0 (%))

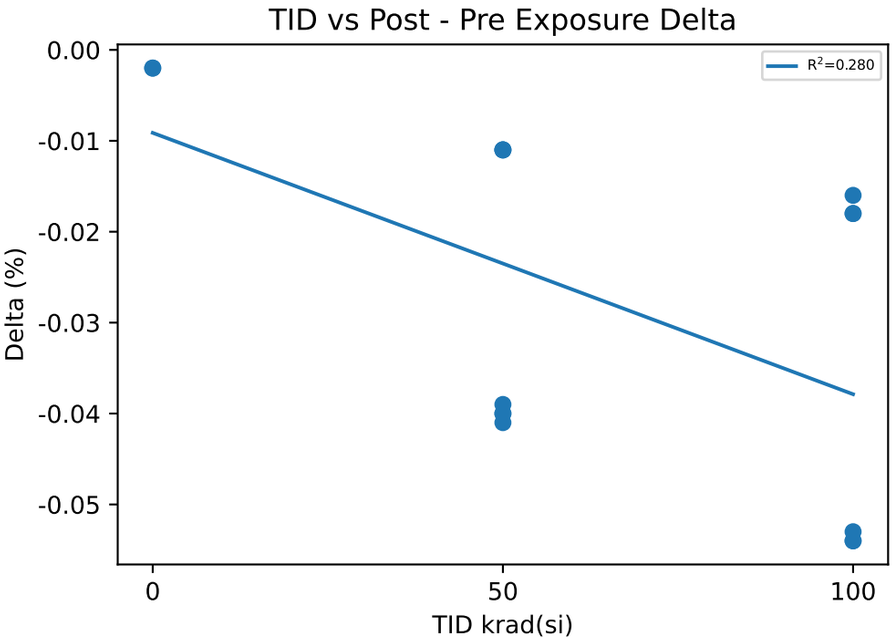
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.548	0.534	-0.014
89	50	Biased	0.549	0.536	-0.013
90	50	Biased	0.55	0.537	-0.013
92	50	Biased	0.559	0.545	-0.014
93	50	Unbiased	0.548	0.539	-0.009
94	50	Unbiased	0.555	0.545	-0.01
95	50	Unbiased	0.545	0.536	-0.009
96	100	Biased	0.552	0.534	-0.018
97	100	Biased	0.547	0.529	-0.018
98	100	Biased	0.545	0.527	-0.018
99	100	Unbiased	0.551	0.535	-0.016
100	100	Unbiased	0.546	0.53	-0.016
101	100	Unbiased	0.545	0.53	-0.015
102	0	Correlation	0.541	0.54	-0.001
103	0	Correlation	0.546	0.545	-0.001

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.541	0.5435	0.546	0.0035355	0.54	0.5425	0.545	0.0035355	-0.001	-0.001	-0.001	0
50	0.545	0.55057	0.559	0.0047909	0.534	0.53886	0.545	0.0044508	-0.014	-0.011714	-0.009	0.0022887
100	0.545	0.54767	0.552	0.0030768	0.527	0.53083	0.535	0.0030605	-0.018	-0.016833	-0.015	0.0013292

Device Test: 6.81 VOL_WDO_2MA(VOL_2mA_WDOB/WDOB/7/3/0/0/2/@VOL_WDO_2MA)





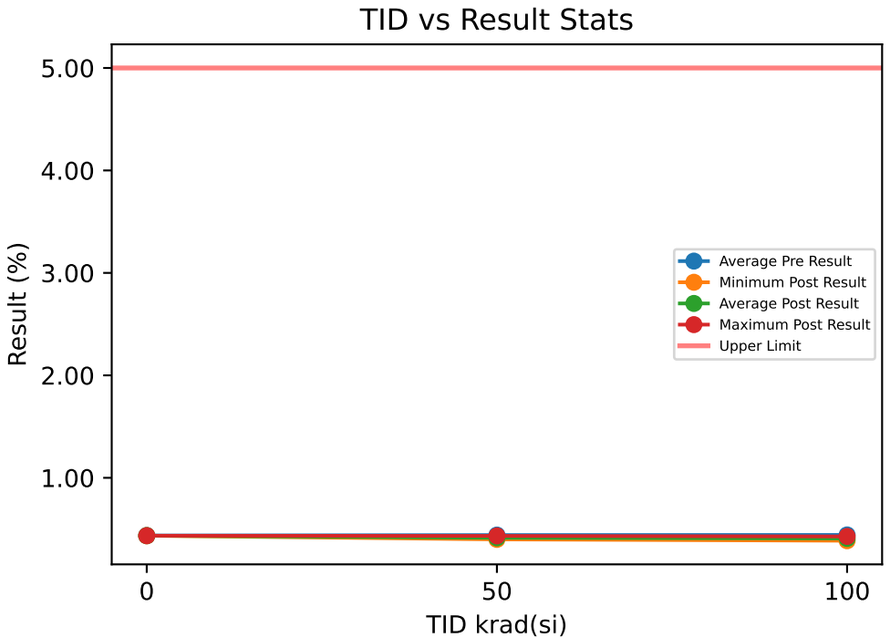
Test Results (Upper Limit = 5.0 (%))

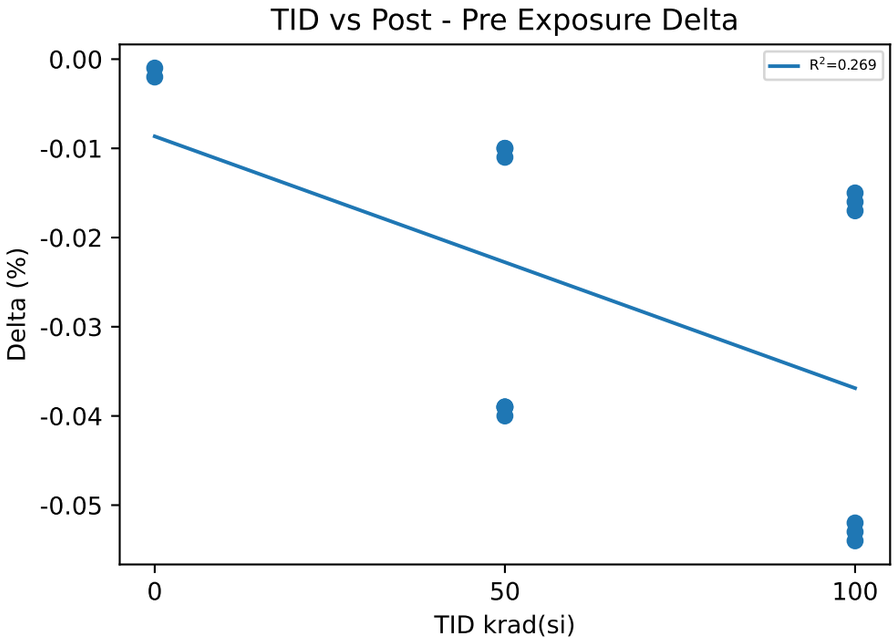
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.436	0.396	-0.04
89	50	Biased	0.439	0.398	-0.041
90	50	Biased	0.439	0.4	-0.039
92	50	Biased	0.441	0.401	-0.04
93	50	Unbiased	0.438	0.427	-0.011
94	50	Unbiased	0.443	0.432	-0.011
95	50	Unbiased	0.438	0.427	-0.011
96	100	Biased	0.444	0.39	-0.054
97	100	Biased	0.437	0.384	-0.053
98	100	Biased	0.436	0.382	-0.054
99	100	Unbiased	0.443	0.425	-0.018
100	100	Unbiased	0.44	0.422	-0.018
101	100	Unbiased	0.438	0.422	-0.016
102	0	Correlation	0.433	0.431	-0.002
103	0	Correlation	0.434	0.432	-0.002

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.433	0.4335	0.434	0.00070711	0.431	0.4315	0.432	0.00070711	-0.002	-0.002	-0.002	0
50	0.436	0.43914	0.443	0.0022678	0.396	0.41157	0.432	0.016154	-0.041	-0.027571	-0.011	0.015512
100	0.436	0.43967	0.444	0.003266	0.382	0.40417	0.425	0.020827	-0.054	-0.0355	-0.016	0.019917

Device Test: 6.82 VOL_PWRGD_2MA(VOL_2mA_PWRGD/PWRGD/7/3/0/0/2/@VOL_PWRGD_2MA)





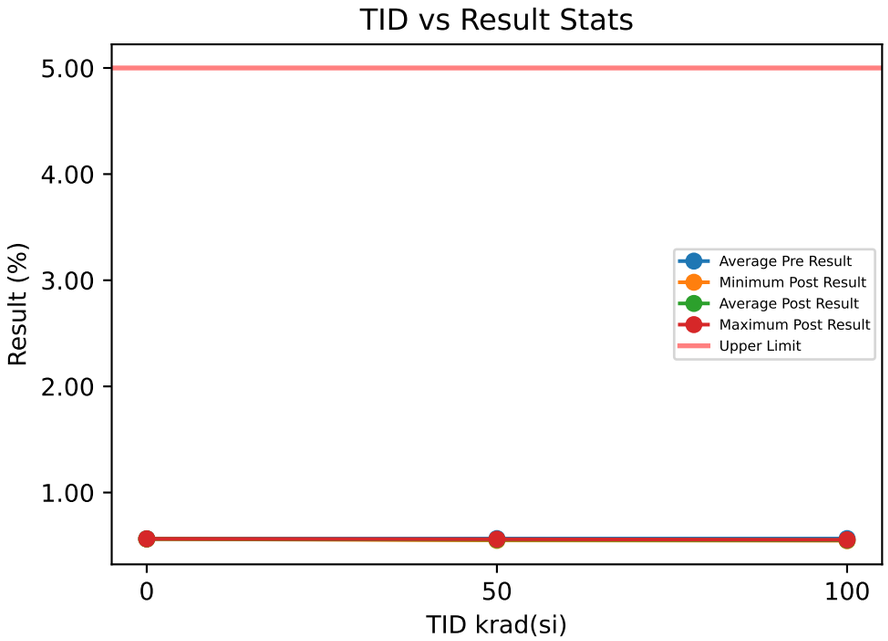
Test Results (Upper Limit = 5.0 (%))

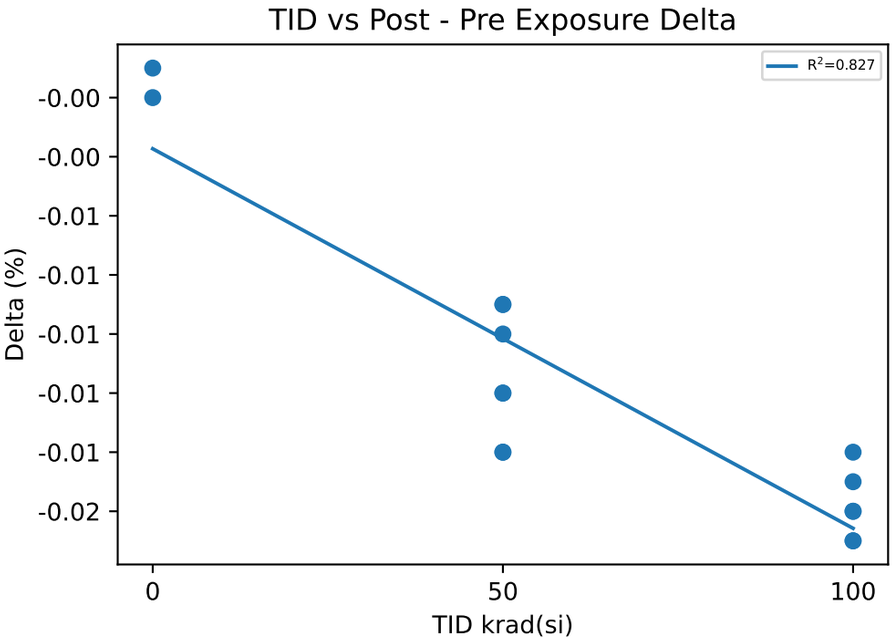
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.438	0.399	-0.039
89	50	Biased	0.44	0.4	-0.04
90	50	Biased	0.441	0.402	-0.039
92	50	Biased	0.445	0.406	-0.039
93	50	Unbiased	0.44	0.43	-0.01
94	50	Unbiased	0.444	0.433	-0.011
95	50	Unbiased	0.44	0.43	-0.01
96	100	Biased	0.447	0.393	-0.054
97	100	Biased	0.44	0.388	-0.052
98	100	Biased	0.439	0.386	-0.053
99	100	Unbiased	0.444	0.428	-0.016
100	100	Unbiased	0.444	0.427	-0.017
101	100	Unbiased	0.441	0.426	-0.015
102	0	Correlation	0.436	0.435	-0.001
103	0	Correlation	0.437	0.435	-0.002

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.436	0.4365	0.437	0.00070711	0.435	0.435	0.435	0	-0.002	-0.0015	-0.001	0.00070711
50	0.438	0.44114	0.445	0.0024785	0.399	0.41429	0.433	0.015819	-0.04	-0.026857	-0.01	0.015464
100	0.439	0.4425	0.447	0.0030166	0.386	0.408	0.428	0.020948	-0.054	-0.0345	-0.015	0.020285

Device Test: 6.83 VOL_RESET_2MA(VOL_2mA_RESETB1/RESETB1/7/14/0/0/2/@VOL_RESET_2MA)





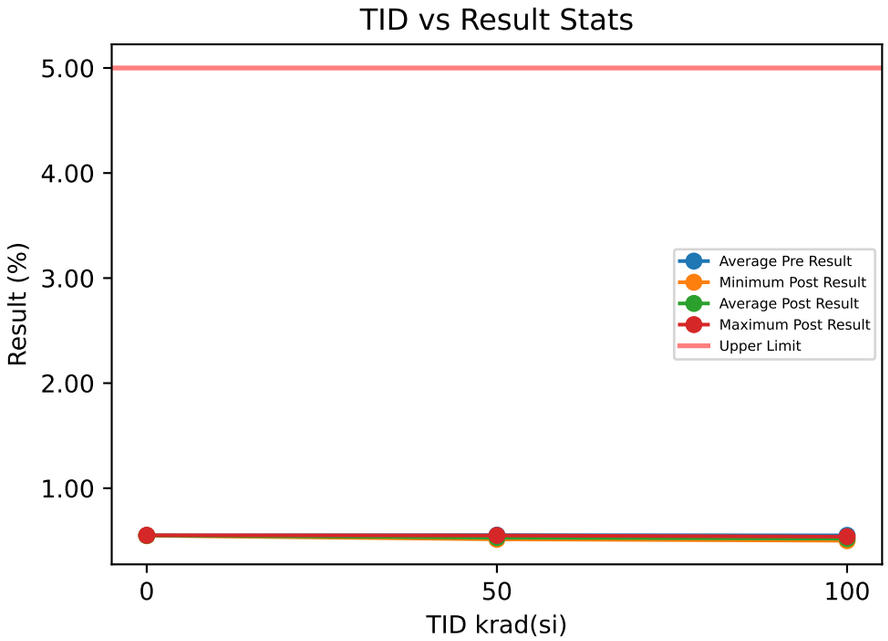
Test Results (Upper Limit = 5.0 (%))

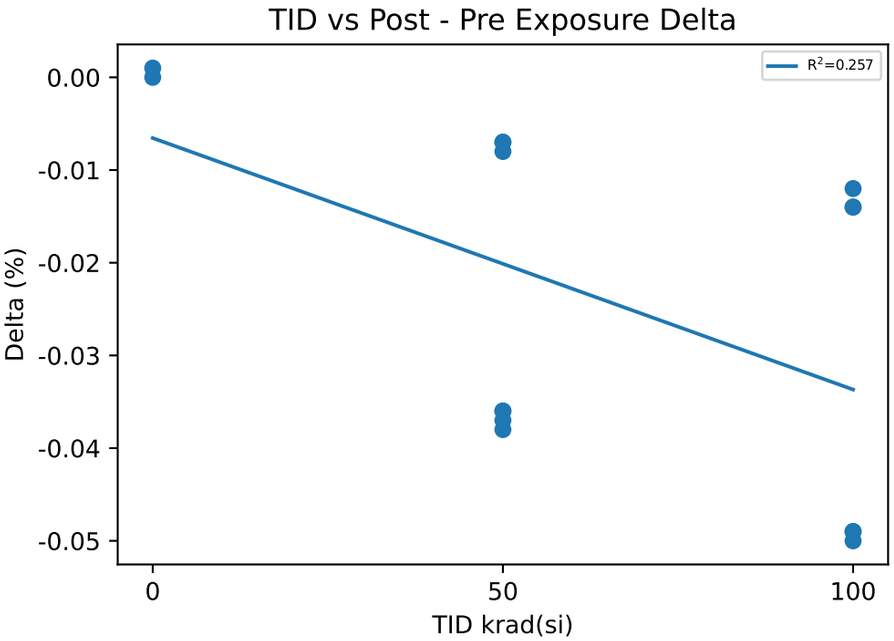
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.563	0.549	-0.014
89	50	Biased	0.566	0.554	-0.012
90	50	Biased	0.569	0.555	-0.014
92	50	Biased	0.563	0.551	-0.012
93	50	Unbiased	0.566	0.557	-0.009
94	50	Unbiased	0.57	0.56	-0.01
95	50	Unbiased	0.566	0.557	-0.009
96	100	Biased	0.569	0.553	-0.016
97	100	Biased	0.563	0.546	-0.017
98	100	Biased	0.563	0.546	-0.017
99	100	Unbiased	0.571	0.555	-0.016
100	100	Unbiased	0.565	0.55	-0.015
101	100	Unbiased	0.566	0.552	-0.014
102	0	Correlation	0.563	0.562	-0.001
103	0	Correlation	0.566	0.564	-0.002

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.563	0.5645	0.566	0.0021213	0.562	0.563	0.564	0.0014142	-0.002	-0.0015	-0.001	0.00070711
50	0.563	0.56614	0.57	0.0026726	0.549	0.55471	0.56	0.0037733	-0.014	-0.011429	-0.009	0.0021492
100	0.563	0.56617	0.571	0.0032506	0.546	0.55033	0.555	0.0037238	-0.017	-0.015833	-0.014	0.001169

Device Test: 6.84 VOL_RESET_2MA(VOL_2mA_RESETB2/RESETB2/7/14/0/0/2/@VOL_RESET_2MA)





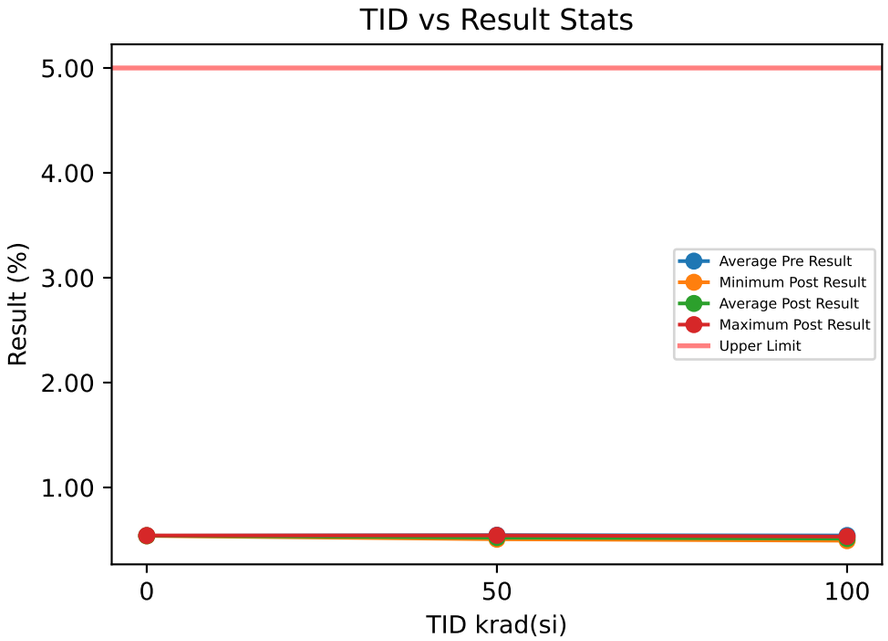
Test Results (Upper Limit = 5.0 (%))

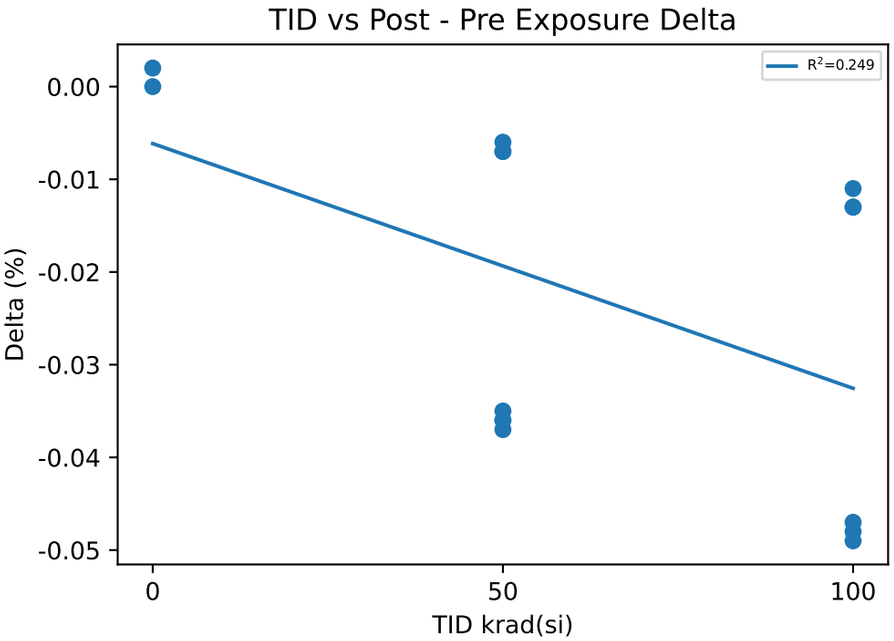
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.551	0.513	-0.038
89	50	Biased	0.553	0.517	-0.036
90	50	Biased	0.553	0.516	-0.037
92	50	Biased	0.558	0.522	-0.036
93	50	Unbiased	0.55	0.543	-0.007
94	50	Unbiased	0.558	0.55	-0.008
95	50	Unbiased	0.549	0.542	-0.007
96	100	Biased	0.552	0.503	-0.049
97	100	Biased	0.551	0.501	-0.05
98	100	Biased	0.549	0.5	-0.049
99	100	Unbiased	0.553	0.539	-0.014
100	100	Unbiased	0.552	0.538	-0.014
101	100	Unbiased	0.549	0.537	-0.012
102	0	Correlation	0.547	0.548	0.001
103	0	Correlation	0.552	0.552	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.547	0.5495	0.552	0.0035355	0.548	0.55	0.552	0.0028284	0	0.0005	0.001	0.00070711
50	0.549	0.55314	0.558	0.0036253	0.513	0.529	0.55	0.015406	-0.038	-0.024143	-0.007	0.015742
100	0.549	0.551	0.553	0.0016733	0.5	0.51967	0.539	0.020116	-0.05	-0.031333	-0.012	0.019735

Device Test: 6.85 VOL_RESET_2MA(VOL_2mA_RESETB3/RESETB3/7/14/0/0/2/@VOL_RESET_2MA)





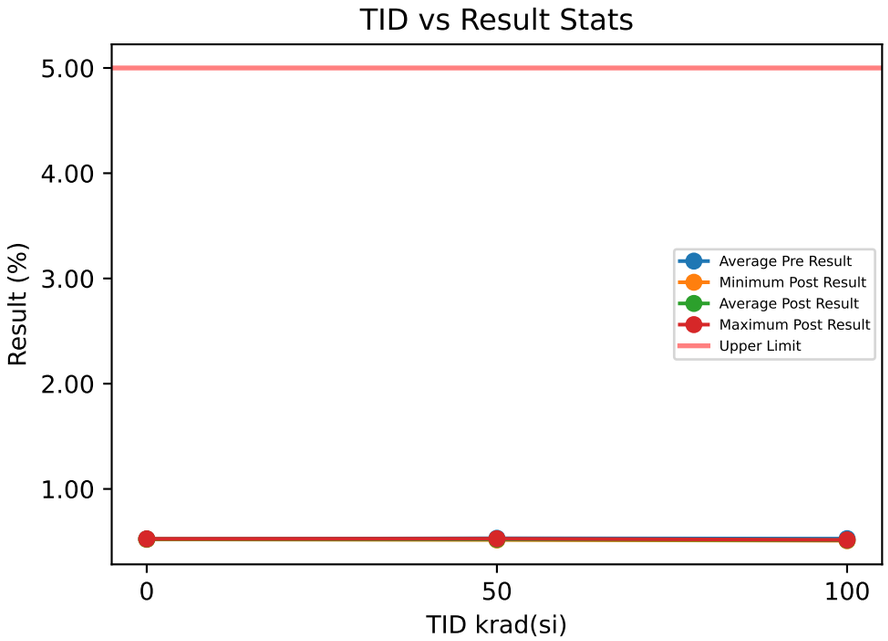
Test Results (Upper Limit = 5.0 (%))

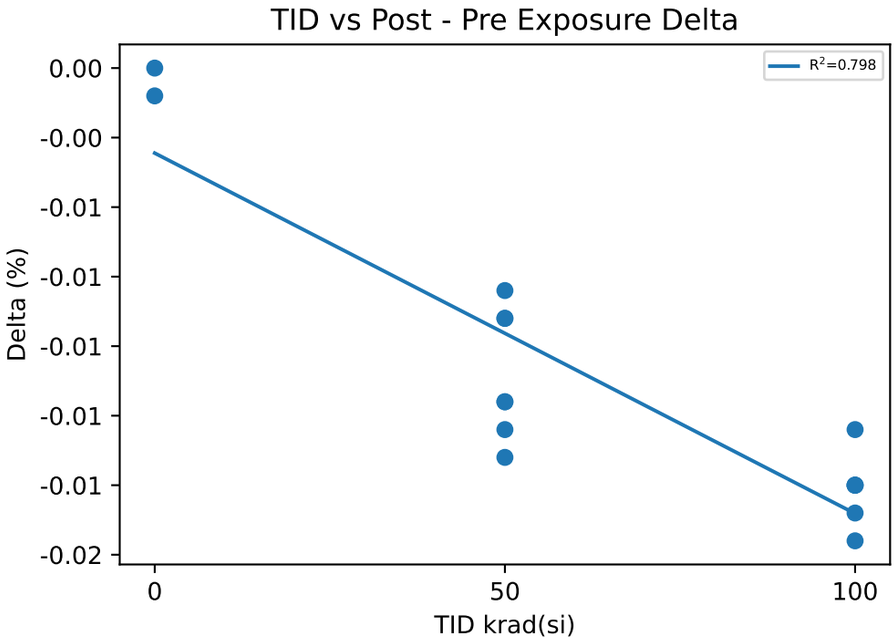
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.543	0.506	-0.037
89	50	Biased	0.545	0.51	-0.035
90	50	Biased	0.545	0.509	-0.036
92	50	Biased	0.55	0.514	-0.036
93	50	Unbiased	0.541	0.535	-0.006
94	50	Unbiased	0.55	0.543	-0.007
95	50	Unbiased	0.54	0.533	-0.007
96	100	Biased	0.544	0.497	-0.047
97	100	Biased	0.541	0.493	-0.048
98	100	Biased	0.541	0.492	-0.049
99	100	Unbiased	0.545	0.532	-0.013
100	100	Unbiased	0.541	0.528	-0.013
101	100	Unbiased	0.54	0.529	-0.011
102	0	Correlation	0.536	0.538	0.002
103	0	Correlation	0.542	0.542	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.536	0.539	0.542	0.0042426	0.538	0.54	0.542	0.0028284	0	0.001	0.002	0.0014142
50	0.54	0.54486	0.55	0.0039761	0.506	0.52143	0.543	0.015065	-0.037	-0.023429	-0.006	0.015693
100	0.54	0.542	0.545	0.002	0.492	0.51183	0.532	0.019651	-0.049	-0.030167	-0.011	0.019559

Device Test: 6.86 VOL_RESET_2MA(VOL_2mA_RESETB4/RESETB4/7/14/0/0/2/@VOL_RESET_2MA)





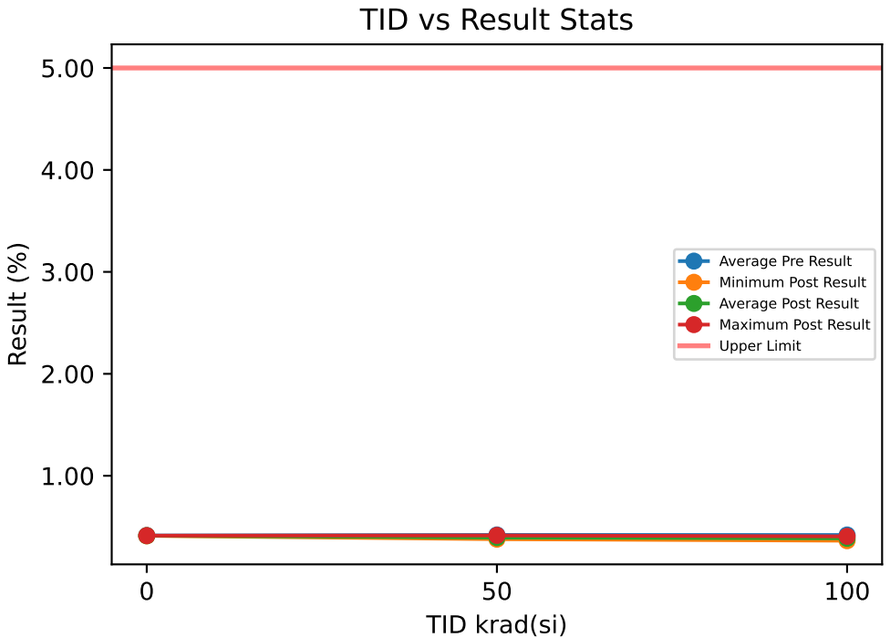
Test Results (Upper Limit = 5.0 (%))

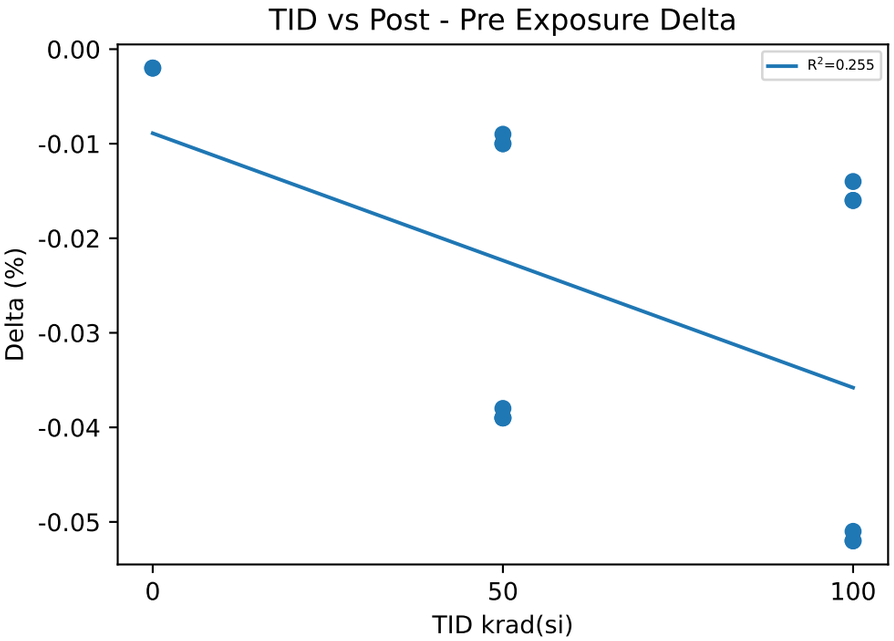
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.529	0.515	-0.014
89	50	Biased	0.53	0.518	-0.012
90	50	Biased	0.531	0.519	-0.012
92	50	Biased	0.539	0.526	-0.013
93	50	Unbiased	0.527	0.519	-0.008
94	50	Unbiased	0.536	0.527	-0.009
95	50	Unbiased	0.526	0.517	-0.009
96	100	Biased	0.531	0.516	-0.015
97	100	Biased	0.527	0.511	-0.016
98	100	Biased	0.525	0.508	-0.017
99	100	Unbiased	0.531	0.516	-0.015
100	100	Unbiased	0.527	0.512	-0.015
101	100	Unbiased	0.525	0.512	-0.013
102	0	Correlation	0.521	0.521	0
103	0	Correlation	0.527	0.526	-0.001

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.521	0.524	0.527	0.0042426	0.521	0.5235	0.526	0.0035355	-0.001	-0.0005	0	0.00070711
50	0.526	0.53114	0.539	0.0047409	0.515	0.52014	0.527	0.0045617	-0.014	-0.011	-0.008	0.0023094
100	0.525	0.52767	0.531	0.0027325	0.508	0.5125	0.516	0.0030822	-0.017	-0.015167	-0.013	0.0013292

Device Test: 6.87 VOL_WDO_2MA(VOL_2mA_WDOB/WDOB/7/14/0/0/2/@VOL_WDO_2MA)





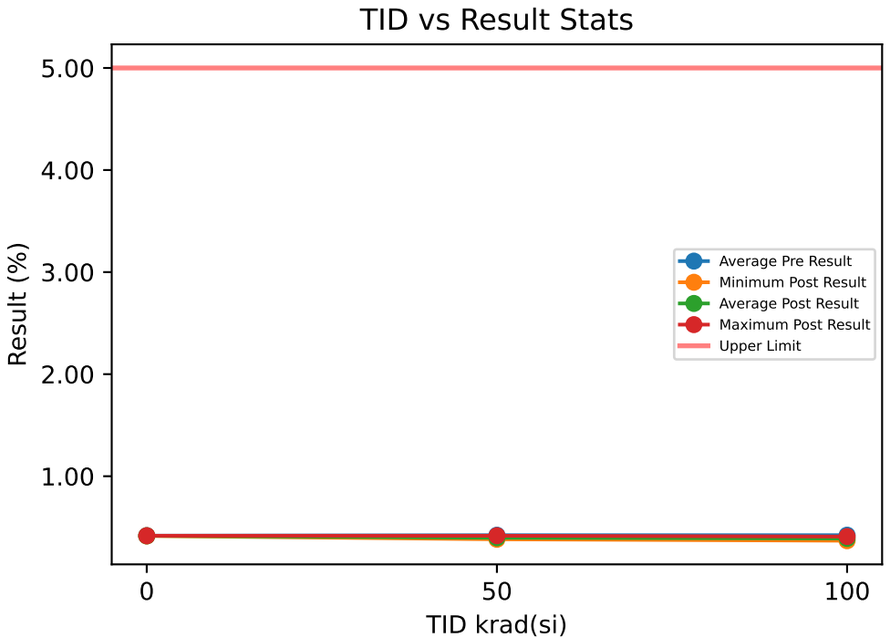
Test Results (Upper Limit = 5.0 (%))

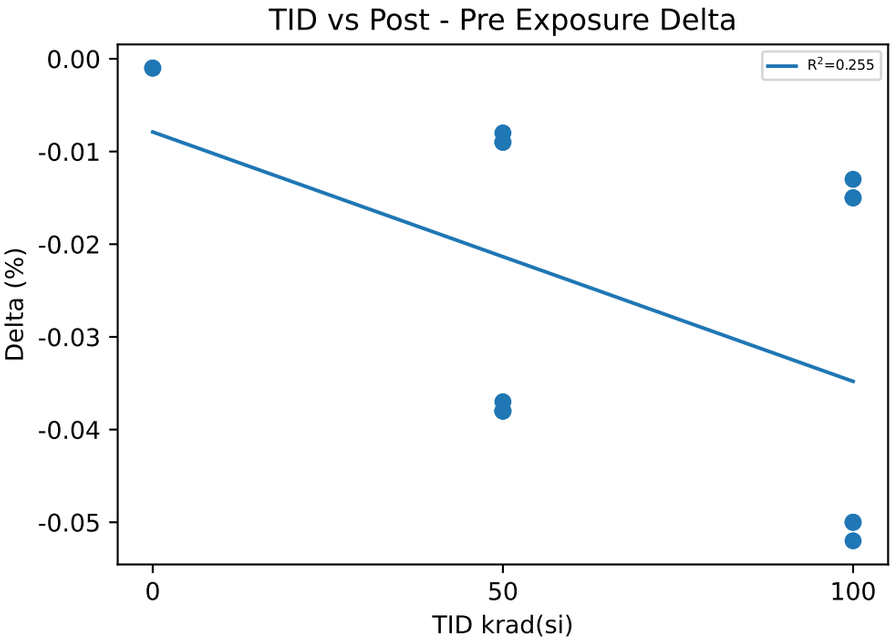
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.417	0.378	-0.039
89	50	Biased	0.419	0.38	-0.039
90	50	Biased	0.42	0.382	-0.038
92	50	Biased	0.422	0.383	-0.039
93	50	Unbiased	0.417	0.408	-0.009
94	50	Unbiased	0.425	0.415	-0.01
95	50	Unbiased	0.418	0.408	-0.01
96	100	Biased	0.424	0.372	-0.052
97	100	Biased	0.417	0.366	-0.051
98	100	Biased	0.415	0.363	-0.052
99	100	Unbiased	0.422	0.406	-0.016
100	100	Unbiased	0.42	0.404	-0.016
101	100	Unbiased	0.418	0.404	-0.014
102	0	Correlation	0.413	0.411	-0.002
103	0	Correlation	0.415	0.413	-0.002

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.413	0.414	0.415	0.0014142	0.411	0.412	0.413	0.0014142	-0.002	-0.002	-0.002	0
50	0.417	0.41971	0.425	0.0029277	0.378	0.39343	0.415	0.016061	-0.039	-0.026286	-0.009	0.015553
100	0.415	0.41933	0.424	0.0033267	0.363	0.38583	0.406	0.020846	-0.052	-0.0335	-0.014	0.019917

Device Test: 6.88 VOL_PWRGD_2MA(VOL_2mA_PWRGD/PWRGD/7/14/0/0/2/@VOL_PWRGD_2MA)





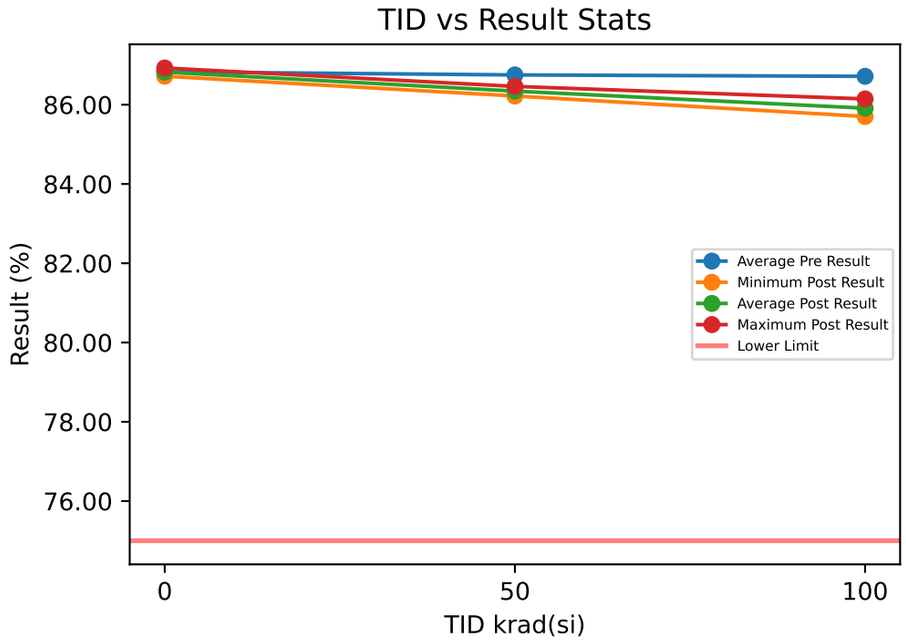
Test Results (Upper Limit = 5.0 (%))

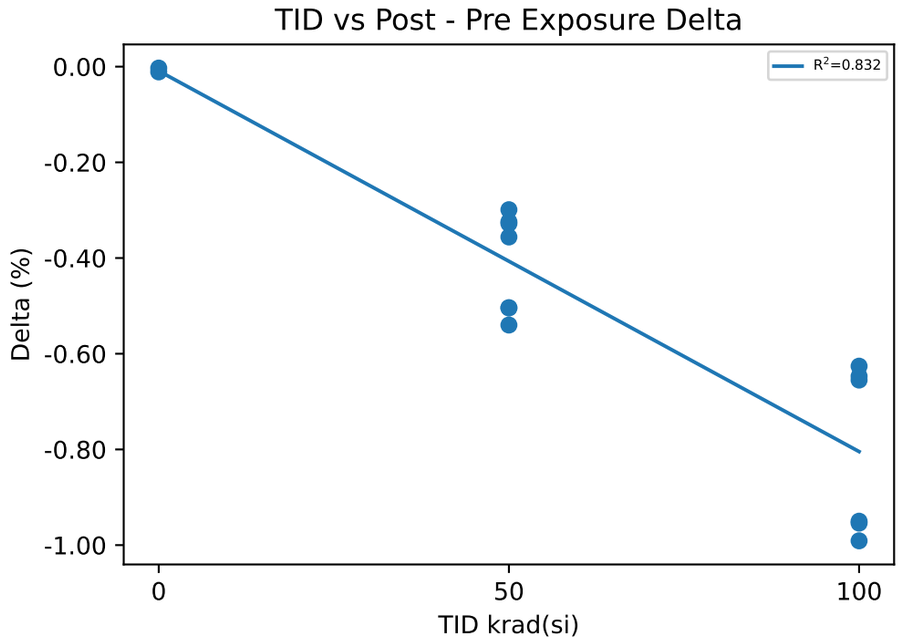
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	0.42	0.382	-0.038
89	50	Biased	0.421	0.383	-0.038
90	50	Biased	0.422	0.384	-0.038
92	50	Biased	0.425	0.388	-0.037
93	50	Unbiased	0.42	0.411	-0.009
94	50	Unbiased	0.426	0.417	-0.009
95	50	Unbiased	0.42	0.412	-0.008
96	100	Biased	0.427	0.375	-0.052
97	100	Biased	0.42	0.37	-0.05
98	100	Biased	0.418	0.368	-0.05
99	100	Unbiased	0.424	0.409	-0.015
100	100	Unbiased	0.424	0.409	-0.015
101	100	Unbiased	0.421	0.408	-0.013
102	0	Correlation	0.416	0.415	-0.001
103	0	Correlation	0.418	0.417	-0.001

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.416	0.417	0.418	0.0014142	0.415	0.416	0.417	0.0014142	-0.001	-0.001	-0.001	0
50	0.42	0.422	0.426	0.0025166	0.382	0.39671	0.417	0.015766	-0.038	-0.025286	-0.008	0.015553
100	0.418	0.42233	0.427	0.003266	0.368	0.38983	0.409	0.02076	-0.052	-0.0325	-0.013	0.019927

Device Test: 6.89 VOH_RESET_10MA(VOH_10mA_RESETB1/RESETB1/1.6/3/0/0/10/@VOH_RESET_10MA)





Test Results (Lower Limit = 75.0 (%))

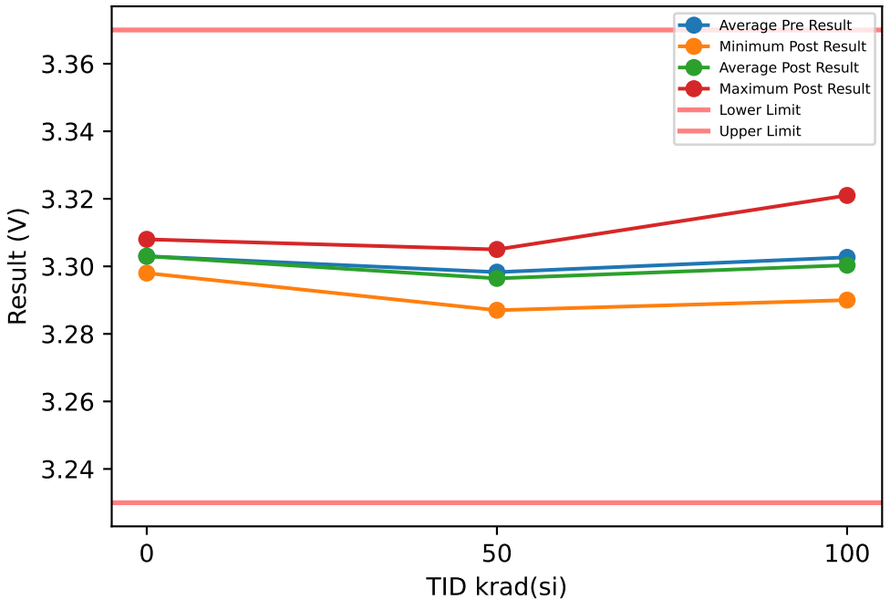
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	86.676	86.377	-0.299
89	50	Biased	86.79	86.462	-0.328
90	50	Biased	86.778	86.454	-0.324
92	50	Biased	86.586	86.23	-0.356
93	50	Unbiased	86.76	86.22	-0.54
94	50	Unbiased	86.798	86.294	-0.504
95	50	Unbiased	86.872	86.368	-0.504
96	100	Biased	86.724	86.077	-0.647
97	100	Biased	86.724	86.069	-0.655
98	100	Biased	86.772	86.146	-0.626
99	100	Unbiased	86.713	85.763	-0.95
100	100	Unbiased	86.671	85.717	-0.954
101	100	Unbiased	86.694	85.703	-0.991
102	0	Correlation	86.93	86.927	-0.003
103	0	Correlation	86.73	86.719	-0.011

Test Statistics (%)

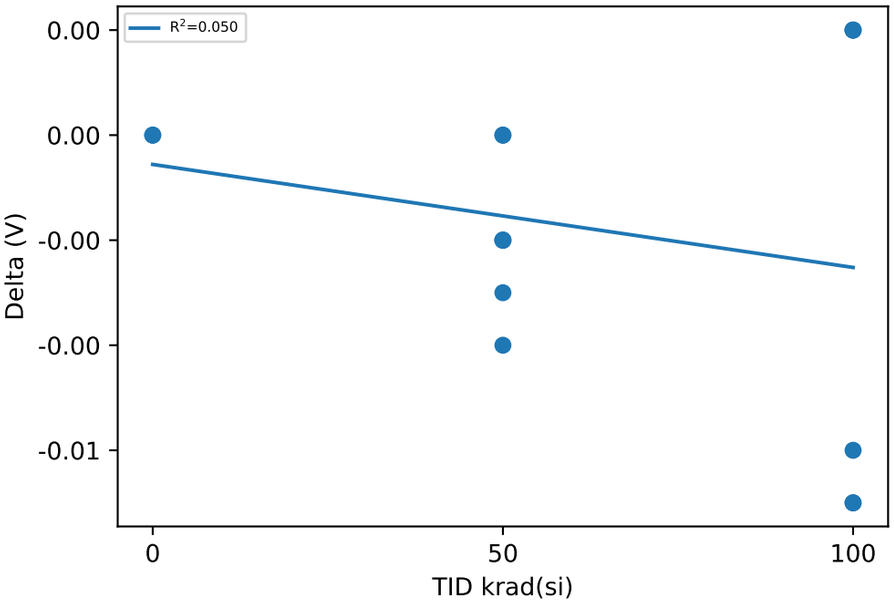
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.73	86.83	86.93	0.14142	86.719	86.823	86.927	0.14708	-0.011	-0.007	-0.003	0.0056569
50	86.586	86.751	86.872	0.093122	86.22	86.344	86.462	0.098792	-0.54	-0.40786	-0.299	0.1032
100	86.671	86.716	86.772	0.034004	85.703	85.913	86.146	0.2052	-0.991	-0.80383	-0.626	0.17738

Device Test: 6.9 VLDO_REG(VLDO/VLDO//3/0/0/0/@VLDO_REG)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



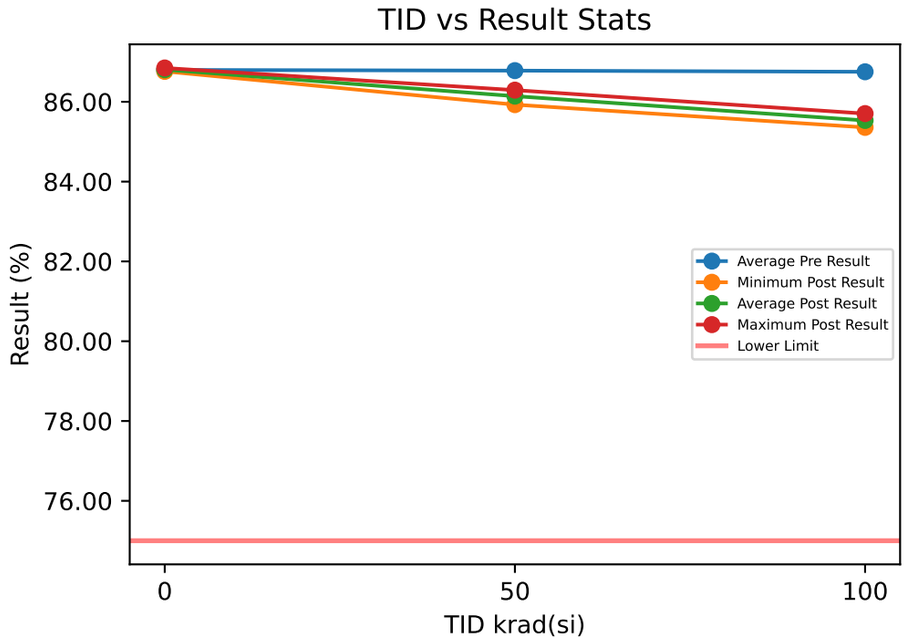
Test Results (Lower Limit = 3.23, Upper Limit = 3.37 (V))

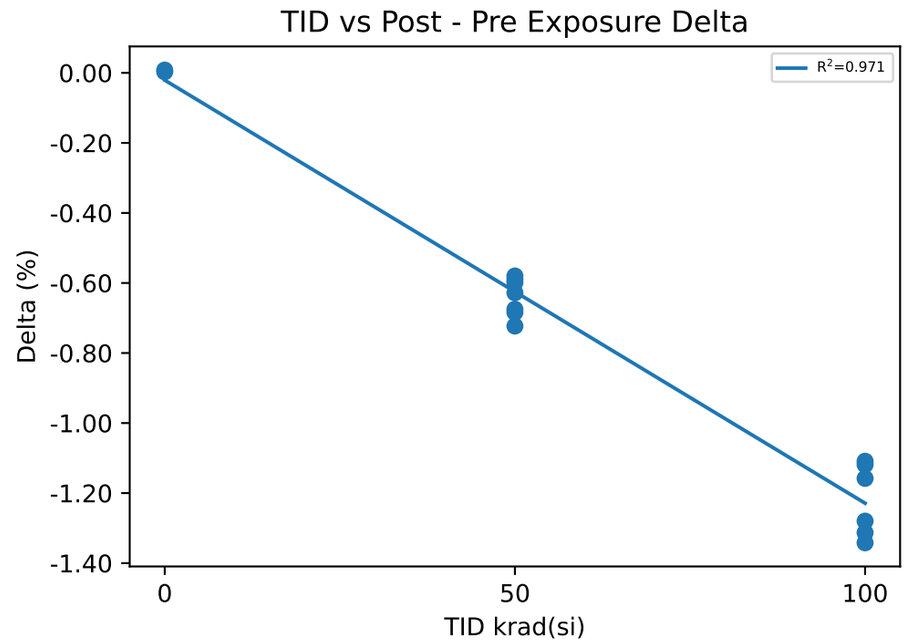
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	3.292	3.292	0
89	50	Biased	3.305	3.303	-0.002
90	50	Biased	3.289	3.287	-0.002
92	50	Biased	3.306	3.304	-0.002
93	50	Unbiased	3.309	3.305	-0.004
94	50	Unbiased	3.291	3.291	0
95	50	Unbiased	3.296	3.293	-0.003
96	100	Biased	3.304	3.297	-0.007
97	100	Biased	3.303	3.297	-0.006
98	100	Biased	3.319	3.321	0.002
99	100	Unbiased	3.298	3.3	0.002
100	100	Unbiased	3.295	3.297	0.002
101	100	Unbiased	3.297	3.29	-0.007
102	0	Correlation	3.308	3.308	0
103	0	Correlation	3.298	3.298	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.298	3.303	3.308	0.0070711	3.298	3.303	3.308	0.0070711	0	0	0	0
50	3.289	3.2983	3.309	0.0081999	3.287	3.2964	3.305	0.0073452	-0.004	-0.0018571	0	0.0014639
100	3.295	3.3027	3.319	0.0087331	3.29	3.3003	3.321	0.010652	-0.007	-0.0023333	0.002	0.004761

Device Test: 6.90 VOH_RESET_10MA(VOH_10mA_RESETB2/RESETB2/1.6/3/0/0/10/@VOH_RESET_10MA)





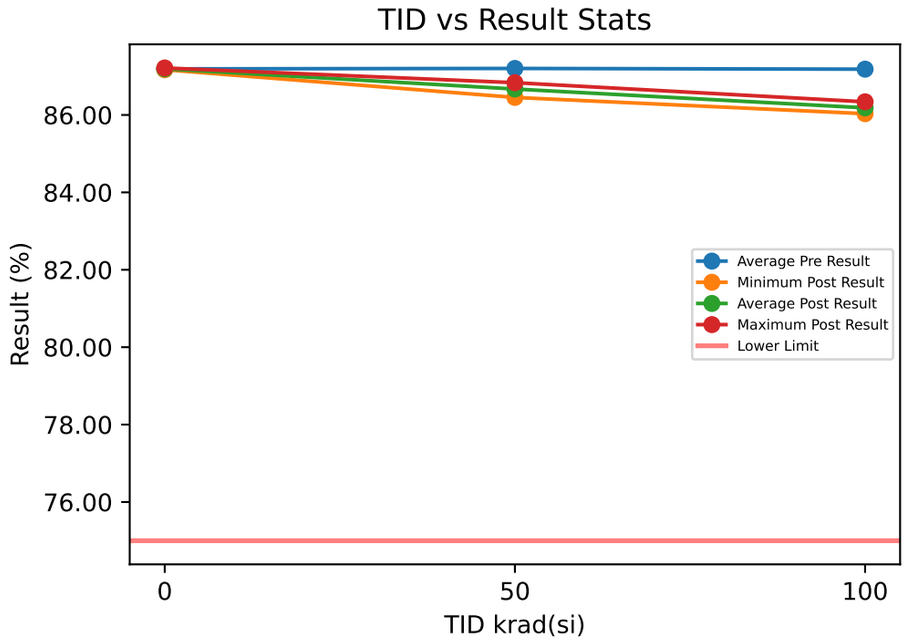
Test Results (Lower Limit = 75.0 (%))

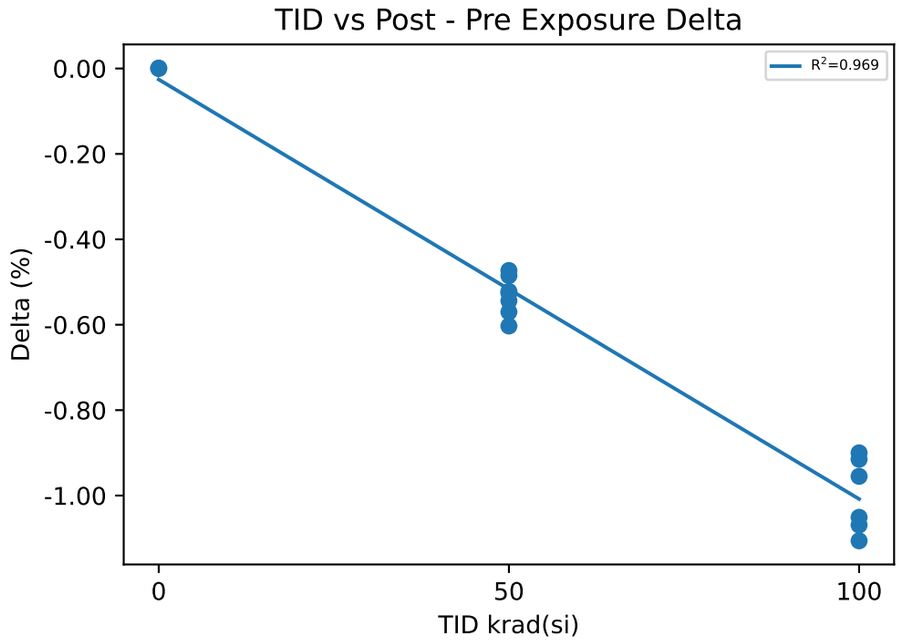
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	86.822	86.223	-0.599
89	50	Biased	86.902	86.227	-0.675
90	50	Biased	86.764	86.08	-0.684
92	50	Biased	86.652	85.929	-0.723
93	50	Unbiased	86.689	86.061	-0.628
94	50	Unbiased	86.873	86.293	-0.58
95	50	Unbiased	86.769	86.179	-0.59
96	100	Biased	86.777	85.497	-1.28
97	100	Biased	86.701	85.359	-1.342
98	100	Biased	86.785	85.472	-1.313
99	100	Unbiased	86.814	85.705	-1.109
100	100	Unbiased	86.686	85.567	-1.119
101	100	Unbiased	86.753	85.595	-1.158
102	0	Correlation	86.84	86.848	0.008
103	0	Correlation	86.759	86.762	0.003

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.759	86.799	86.84	0.057276	86.762	86.805	86.848	0.060811	0.003	0.0055	0.008	0.0035355
50	86.652	86.782	86.902	0.09158	85.929	86.142	86.293	0.12499	-0.723	-0.63986	-0.58	0.054734
100	86.686	86.753	86.814	0.050027	85.359	85.532	85.705	0.11822	-1.342	-1.2202	-1.109	0.10344

Device Test: 6.91 VOH_RESET_10MA(VOH_10mA_RESETB3/RESETB3/1.6/3/0/0/10/@VOH_RESET_10MA)





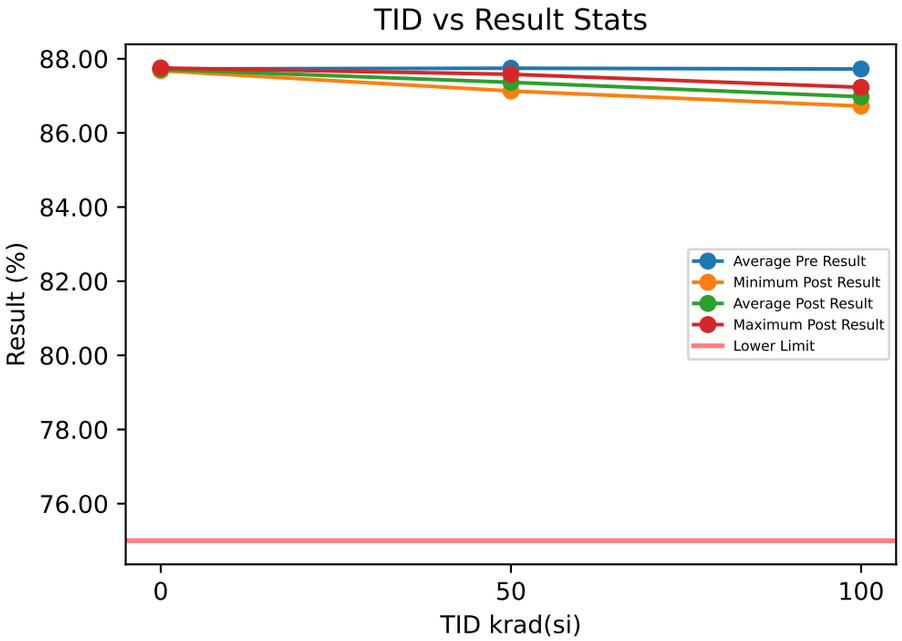
Test Results (Lower Limit = 75.0 (%))

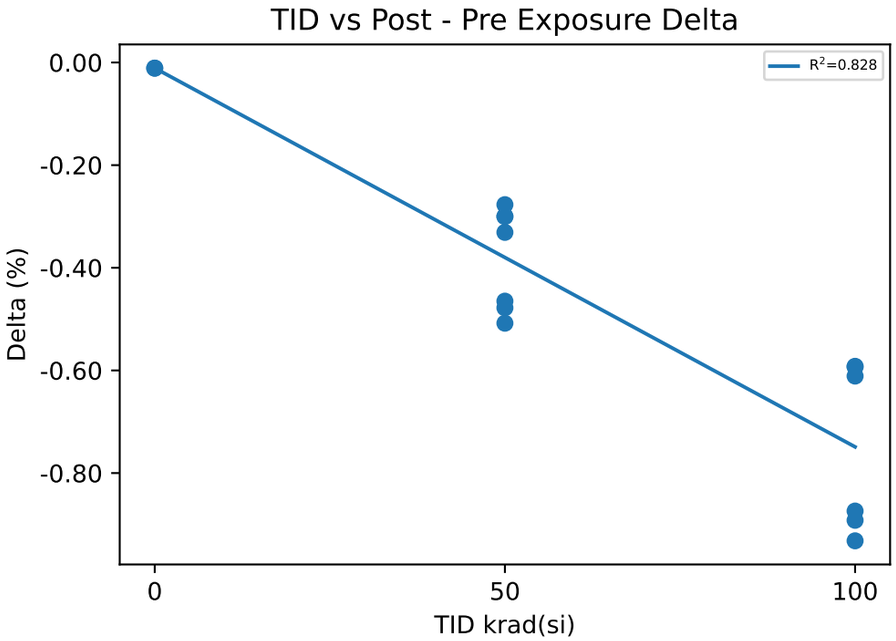
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	87.217	86.691	-0.526
89	50	Biased	87.361	86.817	-0.544
90	50	Biased	87.217	86.647	-0.57
92	50	Biased	87.056	86.453	-0.603
93	50	Unbiased	87.106	86.584	-0.522
94	50	Unbiased	87.307	86.834	-0.473
95	50	Unbiased	87.148	86.663	-0.485
96	100	Biased	87.237	86.168	-1.069
97	100	Biased	87.139	86.033	-1.106
98	100	Biased	87.239	86.188	-1.051
99	100	Unbiased	87.24	86.34	-0.9
100	100	Unbiased	87.145	86.23	-0.915
101	100	Unbiased	87.1	86.145	-0.955
102	0	Correlation	87.213	87.214	0.001
103	0	Correlation	87.169	87.169	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	87.169	87.191	87.213	0.031113	87.169	87.191	87.214	0.03182	0	0.0005	0.001	0.00070711
50	87.056	87.202	87.361	0.10817	86.453	86.67	86.834	0.13166	-0.603	-0.53186	-0.473	0.045561
100	87.1	87.183	87.24	0.062561	86.033	86.184	86.34	0.10104	-1.106	-0.99933	-0.9	0.087

Device Test: 6.92 VOH_RESET_10MA(VOH_10mA_RESETB4/RESETB4/1.6/3/0/0/10/@VOH_RESET_10MA)





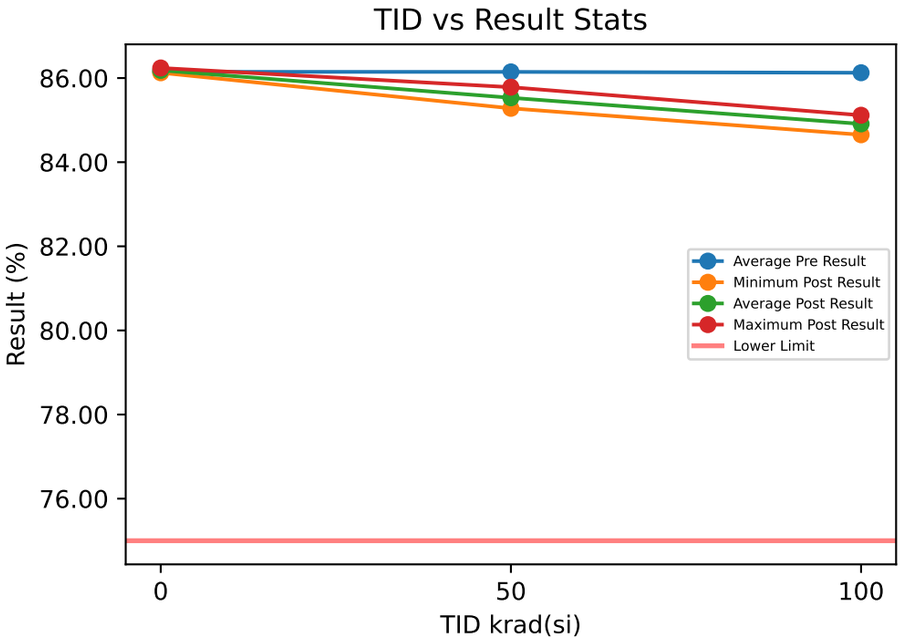
Test Results (Lower Limit = 75.0 (%))

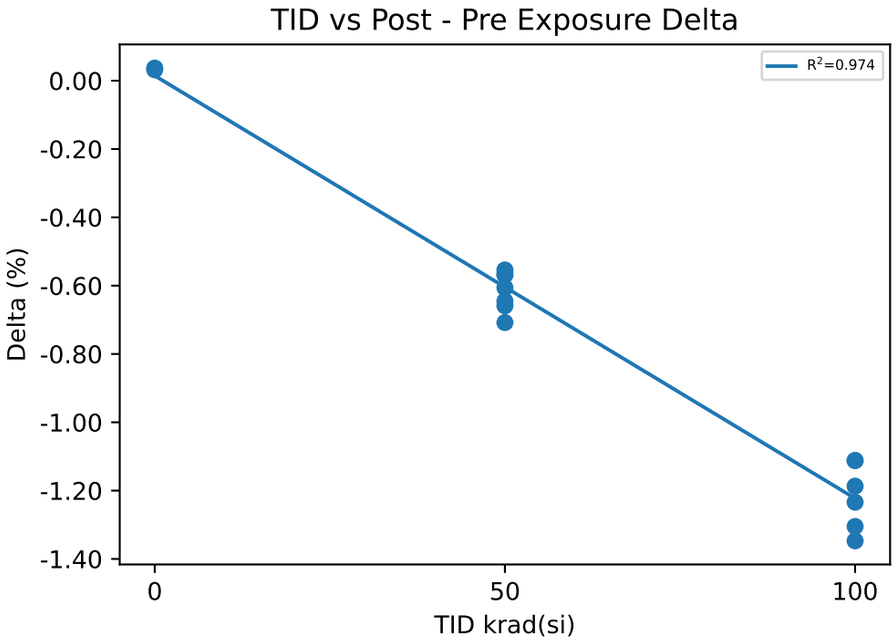
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	87.769	87.492	-0.277
89	50	Biased	87.881	87.581	-0.3
90	50	Biased	87.783	87.483	-0.3
92	50	Biased	87.601	87.27	-0.331
93	50	Unbiased	87.638	87.13	-0.508
94	50	Unbiased	87.851	87.386	-0.465
95	50	Unbiased	87.684	87.206	-0.478
96	100	Biased	87.821	87.229	-0.592
97	100	Biased	87.677	87.066	-0.611
98	100	Biased	87.738	87.145	-0.593
99	100	Unbiased	87.783	86.909	-0.874
100	100	Unbiased	87.668	86.776	-0.892
101	100	Unbiased	87.654	86.722	-0.932
102	0	Correlation	87.762	87.751	-0.011
103	0	Correlation	87.69	87.679	-0.011

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	87.69	87.726	87.762	0.050912	87.679	87.715	87.751	0.050912	-0.011	-0.011	-0.011	0
50	87.601	87.744	87.881	0.10618	87.13	87.364	87.581	0.16667	-0.508	-0.37986	-0.277	0.099182
100	87.654	87.724	87.821	0.068307	86.722	86.974	87.229	0.20477	-0.932	-0.749	-0.592	0.16589

Device Test: 6.93 VOH_WDO_10MA(VOH_10mA_WDOB/WDOB/1.6/3/0/0/10/@VOH_WDO_10MA)





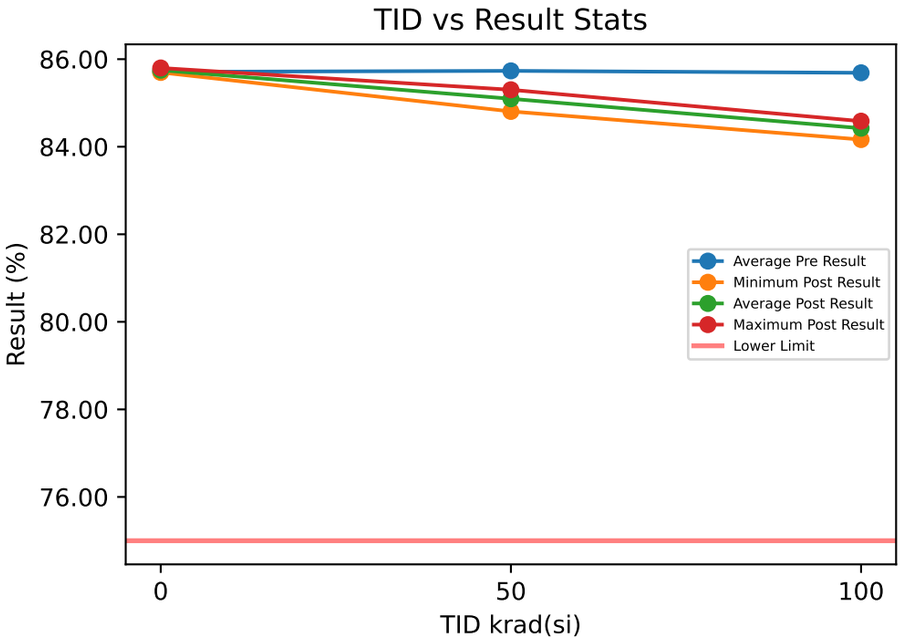
Test Results (Lower Limit = 75.0 (%))

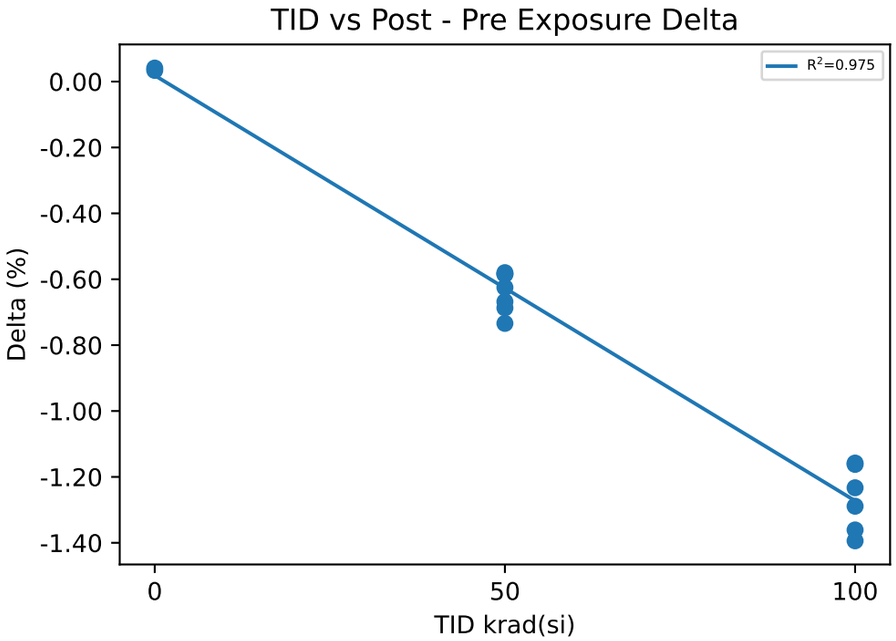
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	86.199	85.632	-0.567
89	50	Biased	86.321	85.676	-0.645
90	50	Biased	86.199	85.54	-0.659
92	50	Biased	85.989	85.281	-0.708
93	50	Unbiased	85.988	85.382	-0.606
94	50	Unbiased	86.337	85.783	-0.554
95	50	Unbiased	85.995	85.426	-0.569
96	100	Biased	86.279	85.045	-1.234
97	100	Biased	85.999	84.652	-1.347
98	100	Biased	86.121	84.816	-1.305
99	100	Unbiased	86.228	85.116	-1.112
100	100	Unbiased	86.137	85.025	-1.112
101	100	Unbiased	85.995	84.808	-1.187
102	0	Correlation	86.203	86.24	0.037
103	0	Correlation	86.094	86.126	0.032

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.094	86.148	86.203	0.077075	86.126	86.183	86.24	0.08061	0.032	0.0345	0.037	0.0035355
50	85.988	86.147	86.337	0.15553	85.281	85.531	85.783	0.1782	-0.708	-0.61543	-0.554	0.057309
100	85.995	86.127	86.279	0.11597	84.652	84.91	85.116	0.17871	-1.347	-1.2162	-1.112	0.097856

Device Test: 6.94 VOH_PWRGD_10MA(VOH_10mA_PWRGD/PWRGD/1.6/3/0/0/10/@VOH_PWRGD_10MA)





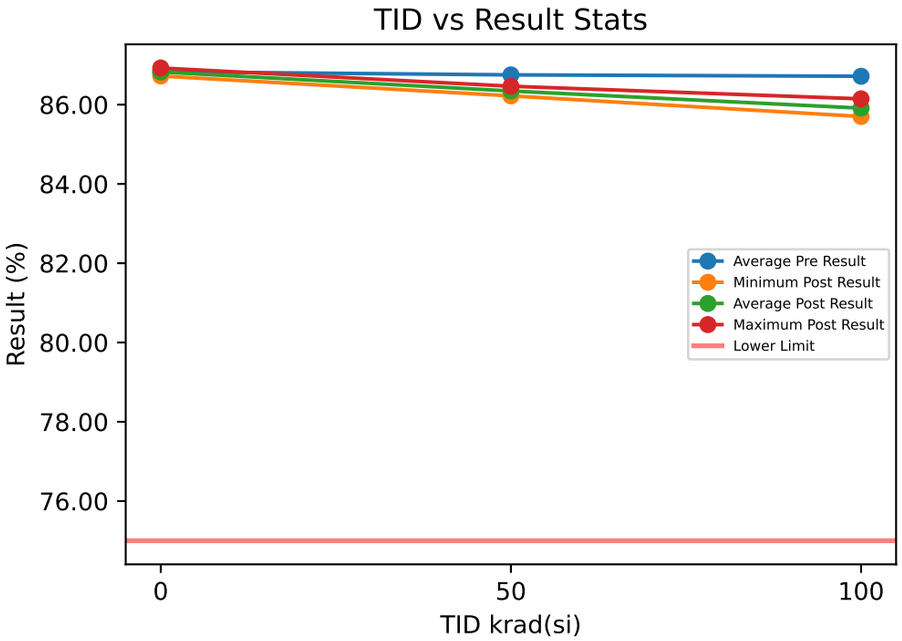
Test Results (Lower Limit = 75.0 (%))

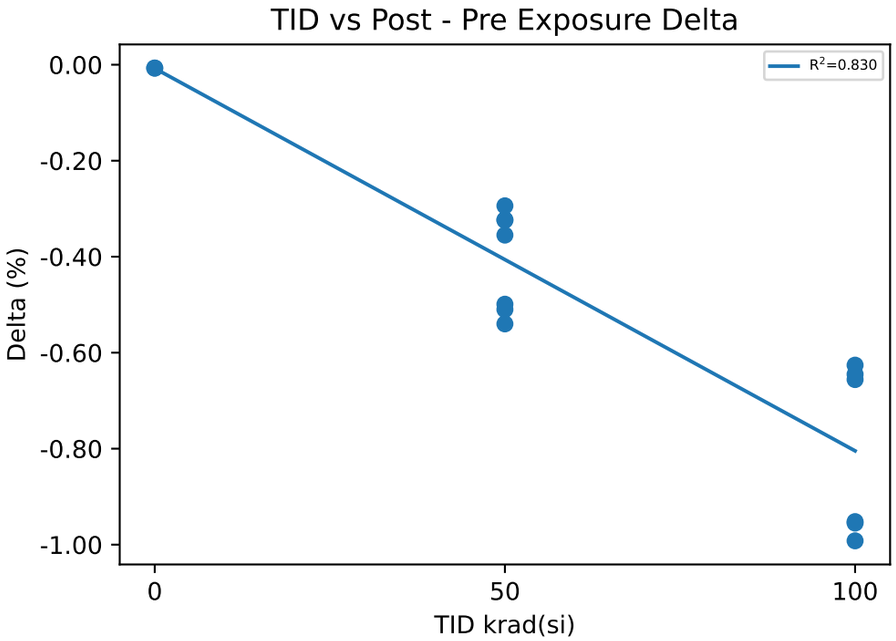
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	85.84	85.256	-0.584
89	50	Biased	85.891	85.223	-0.668
90	50	Biased	85.76	85.073	-0.687
92	50	Biased	85.541	84.807	-0.734
93	50	Unbiased	85.584	84.959	-0.625
94	50	Unbiased	85.881	85.301	-0.58
95	50	Unbiased	85.634	85.049	-0.585
96	100	Biased	85.784	84.495	-1.289
97	100	Biased	85.558	84.164	-1.394
98	100	Biased	85.723	84.362	-1.361
99	100	Unbiased	85.746	84.584	-1.162
100	100	Unbiased	85.68	84.522	-1.158
101	100	Unbiased	85.641	84.408	-1.233
102	0	Correlation	85.758	85.799	0.041
103	0	Correlation	85.663	85.697	0.034

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	85.663	85.71	85.758	0.067175	85.697	85.748	85.799	0.072125	0.034	0.0375	0.041	0.0049497
50	85.541	85.733	85.891	0.14601	84.807	85.095	85.301	0.17738	-0.734	-0.63757	-0.58	0.060241
100	85.558	85.689	85.784	0.08121	84.164	84.422	84.584	0.14962	-1.394	-1.2662	-1.158	0.099506

Device Test: 6.95 VOH_RESET_10MA(VOH_10mA_RESETB1/RESETB1/1.6/14/0/0/10/@VOH_RESET_10MA)





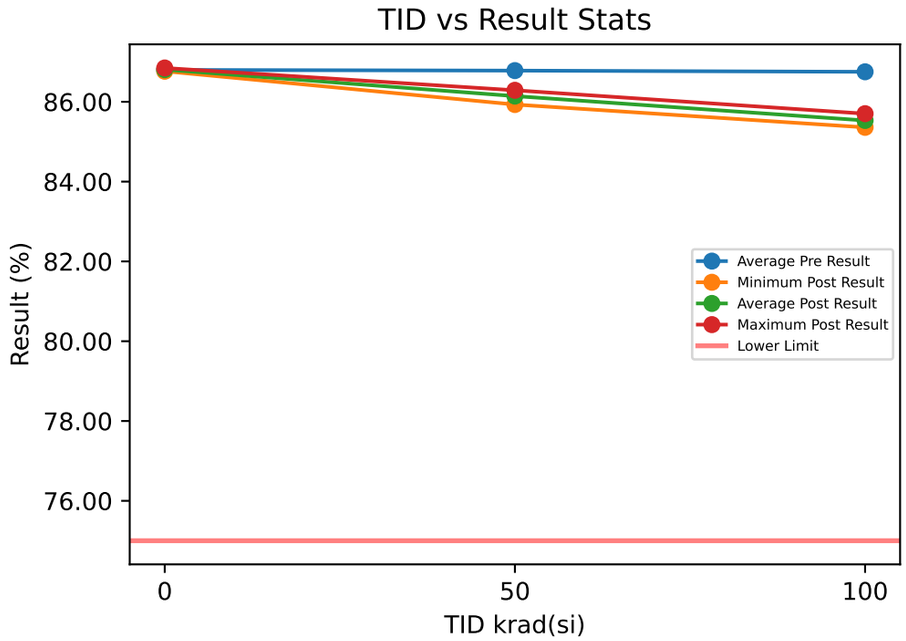
Test Results (Lower Limit = 75.0 (%))

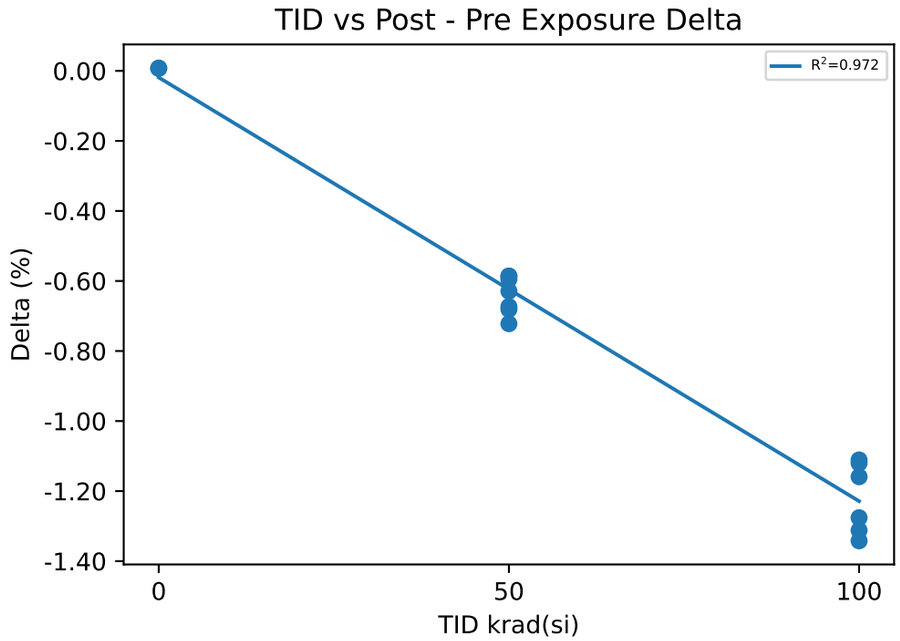
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	86.674	86.38	-0.294
89	50	Biased	86.788	86.464	-0.324
90	50	Biased	86.777	86.454	-0.323
92	50	Biased	86.587	86.232	-0.355
93	50	Unbiased	86.761	86.221	-0.54
94	50	Unbiased	86.799	86.289	-0.51
95	50	Unbiased	86.871	86.372	-0.499
96	100	Biased	86.725	86.08	-0.645
97	100	Biased	86.725	86.069	-0.656
98	100	Biased	86.772	86.146	-0.626
99	100	Unbiased	86.712	85.76	-0.952
100	100	Unbiased	86.669	85.714	-0.955
101	100	Unbiased	86.693	85.701	-0.992
102	0	Correlation	86.932	86.925	-0.007
103	0	Correlation	86.729	86.722	-0.007

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.729	86.831	86.932	0.14354	86.722	86.823	86.925	0.14354	-0.007	-0.007	-0.007	0
50	86.587	86.751	86.871	0.092803	86.221	86.345	86.464	0.099395	-0.54	-0.40643	-0.294	0.10502
100	86.669	86.716	86.772	0.034791	85.701	85.912	86.146	0.2071	-0.992	-0.80433	-0.626	0.17828

Device Test: 6.96 VOH_RESET_10MA(VOH_10mA_RESETB2/RESETB2/1.6/14/0/0/10/@VOH_RESET_10MA)





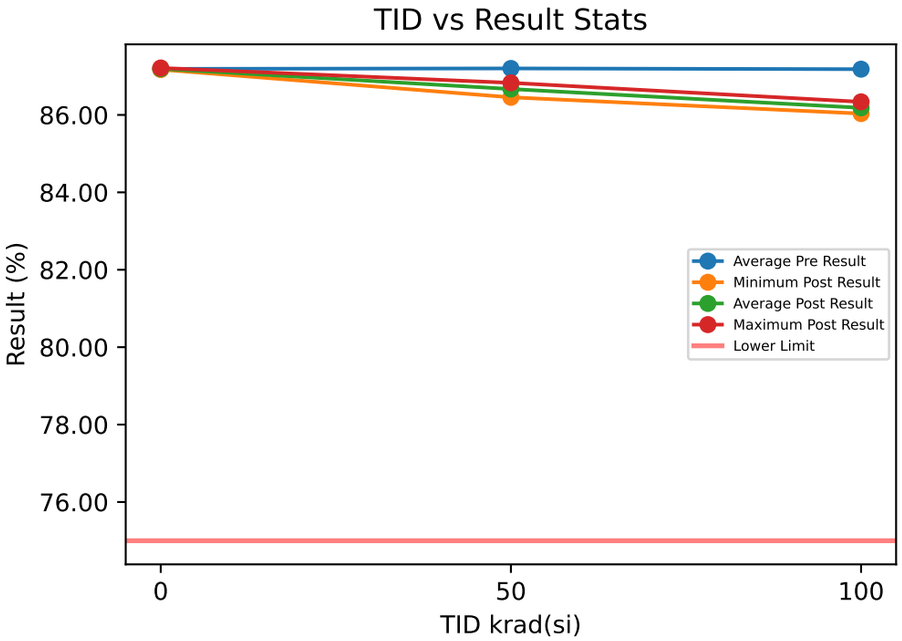
Test Results (Lower Limit = 75.0 (%))

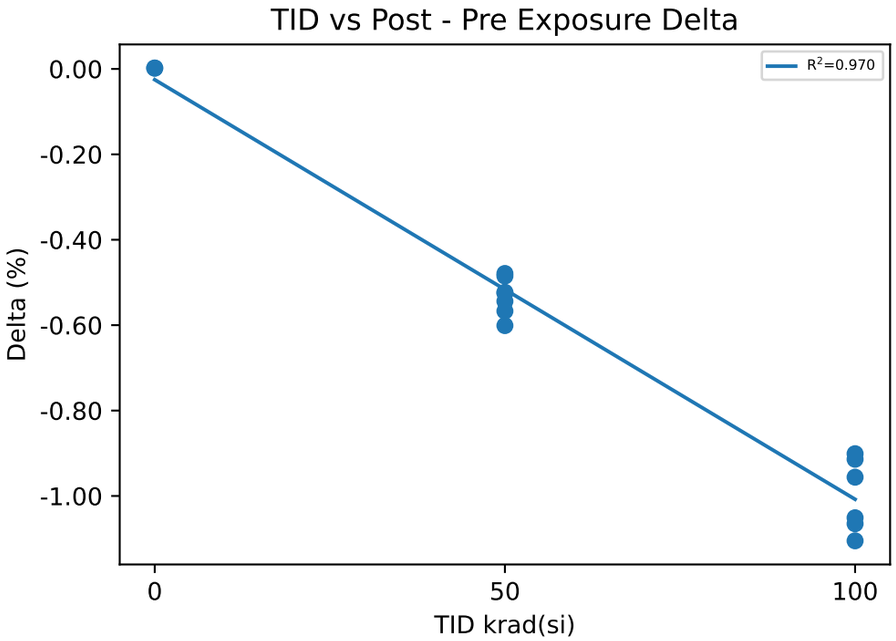
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	86.821	86.226	-0.595
89	50	Biased	86.902	86.229	-0.673
90	50	Biased	86.763	86.082	-0.681
92	50	Biased	86.654	85.932	-0.722
93	50	Unbiased	86.691	86.062	-0.629
94	50	Unbiased	86.875	86.289	-0.586
95	50	Unbiased	86.768	86.182	-0.586
96	100	Biased	86.777	85.501	-1.276
97	100	Biased	86.702	85.36	-1.342
98	100	Biased	86.784	85.472	-1.312
99	100	Unbiased	86.814	85.703	-1.111
100	100	Unbiased	86.685	85.565	-1.12
101	100	Unbiased	86.752	85.593	-1.159
102	0	Correlation	86.84	86.848	0.008
103	0	Correlation	86.759	86.766	0.007

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.759	86.799	86.84	0.057276	86.766	86.807	86.848	0.057983	0.007	0.0075	0.008	0.00070711
50	86.654	86.782	86.902	0.091097	85.932	86.143	86.289	0.12378	-0.722	-0.63886	-0.586	0.053949
100	86.685	86.752	86.814	0.049963	85.36	85.532	85.703	0.11679	-1.342	-1.22	-1.111	0.10206

Device Test: 6.97 VOH_RESET_10MA(VOH_10mA_RESETB3/RESETB3/1.6/14/0/0/10/@VOH_RESET_10MA)





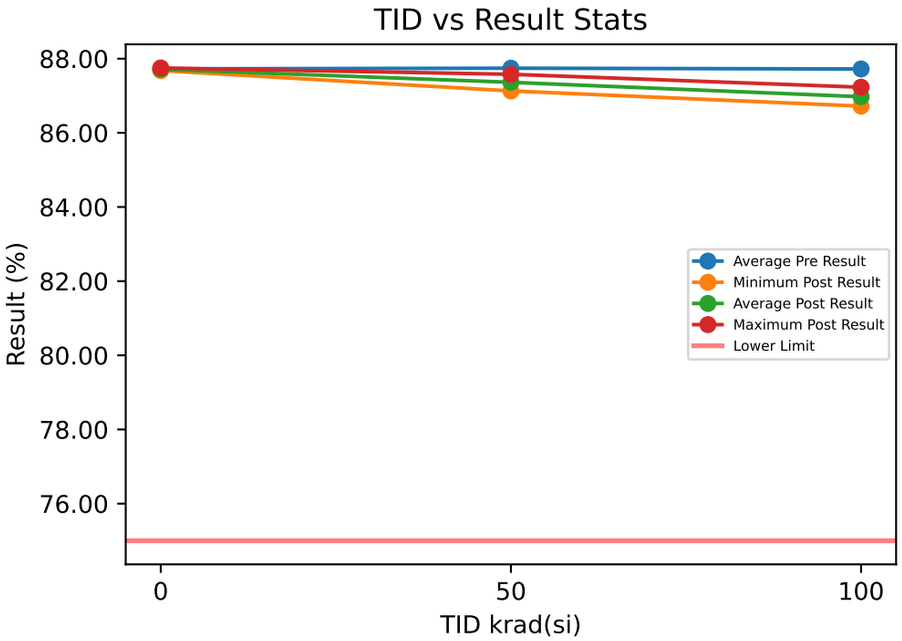
Test Results (Lower Limit = 75.0 (%))

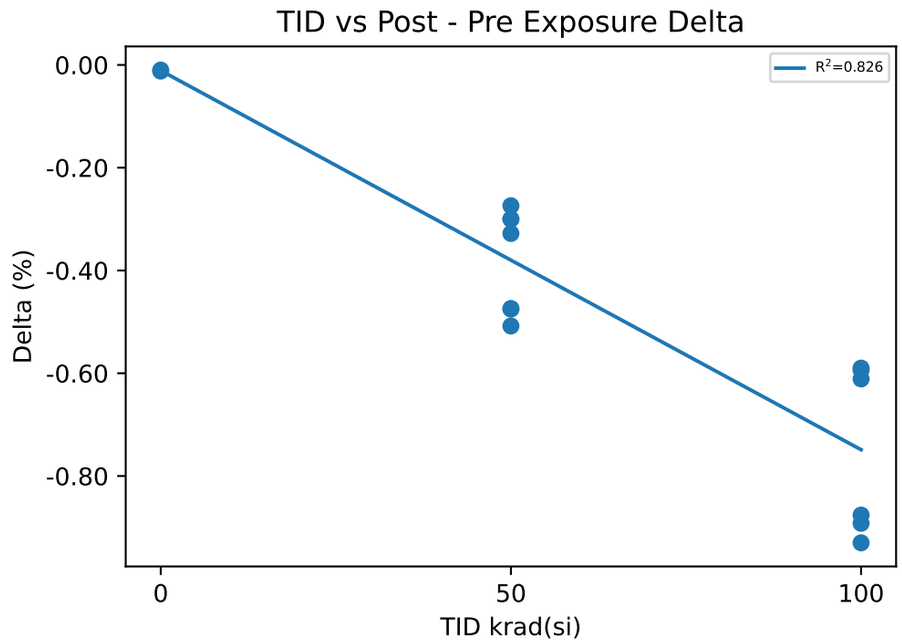
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	87.216	86.691	-0.525
89	50	Biased	87.36	86.816	-0.544
90	50	Biased	87.214	86.647	-0.567
92	50	Biased	87.056	86.455	-0.601
93	50	Unbiased	87.105	86.582	-0.523
94	50	Unbiased	87.308	86.829	-0.479
95	50	Unbiased	87.147	86.662	-0.485
96	100	Biased	87.235	86.17	-1.065
97	100	Biased	87.14	86.035	-1.105
98	100	Biased	87.239	86.188	-1.051
99	100	Unbiased	87.239	86.338	-0.901
100	100	Unbiased	87.142	86.228	-0.914
101	100	Unbiased	87.098	86.142	-0.956
102	0	Correlation	87.211	87.213	0.002
103	0	Correlation	87.17	87.172	0.002

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	87.17	87.191	87.211	0.028991	87.172	87.192	87.213	0.028991	0.002	0.002	0.002	0
50	87.056	87.201	87.36	0.10823	86.455	86.669	86.829	0.13012	-0.601	-0.532	-0.479	0.043355
100	87.098	87.182	87.239	0.062812	86.035	86.183	86.338	0.099827	-1.105	-0.99867	-0.901	0.085992

Device Test: 6.98 VOH_RESET_10MA(VOH_10mA_RESETB4/RESETB4/1.6/14/0/0/10/@VOH_RESET_10MA)





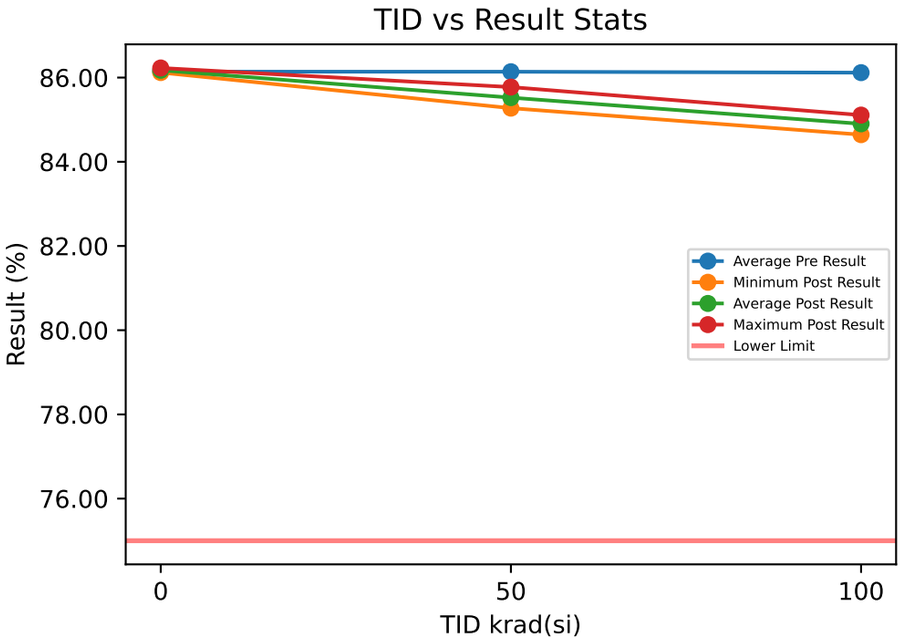
Test Results (Lower Limit = 75.0 (%))

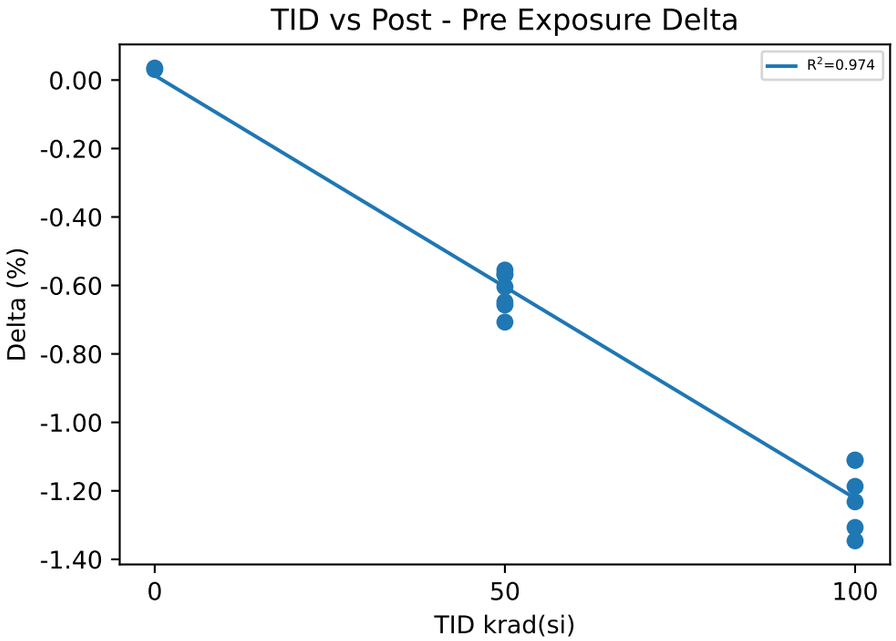
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	87.767	87.493	-0.274
89	50	Biased	87.879	87.579	-0.3
90	50	Biased	87.781	87.481	-0.3
92	50	Biased	87.6	87.272	-0.328
93	50	Unbiased	87.638	87.13	-0.508
94	50	Unbiased	87.853	87.379	-0.474
95	50	Unbiased	87.681	87.206	-0.475
96	100	Biased	87.82	87.23	-0.59
97	100	Biased	87.677	87.066	-0.611
98	100	Biased	87.737	87.143	-0.594
99	100	Unbiased	87.781	86.905	-0.876
100	100	Unbiased	87.667	86.775	-0.892
101	100	Unbiased	87.65	86.72	-0.93
102	0	Correlation	87.761	87.749	-0.012
103	0	Correlation	87.69	87.68	-0.01

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	87.69	87.725	87.761	0.050205	87.68	87.715	87.749	0.04879	-0.012	-0.011	-0.01	0.0014142
50	87.6	87.743	87.879	0.10641	87.13	87.363	87.579	0.16581	-0.508	-0.37986	-0.274	0.10082
100	87.65	87.722	87.82	0.068621	86.72	86.973	87.23	0.20564	-0.93	-0.74883	-0.59	0.16595

Device Test: 6.99 VOH_WDO_10MA(VOH_10mA_WDOB/WDOB/1.6/14/0/0/10/@VOH_WDO_10MA)





Test Results (Lower Limit = 75.0 (%))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
88	50	Biased	86.192	85.624	-0.568
89	50	Biased	86.315	85.667	-0.648
90	50	Biased	86.19	85.533	-0.657
92	50	Biased	85.981	85.274	-0.707
93	50	Unbiased	85.979	85.375	-0.604
94	50	Unbiased	86.329	85.774	-0.555
95	50	Unbiased	85.987	85.419	-0.568
96	100	Biased	86.27	85.038	-1.232
97	100	Biased	85.99	84.644	-1.346
98	100	Biased	86.111	84.804	-1.307
99	100	Unbiased	86.219	85.109	-1.11
100	100	Unbiased	86.127	85.016	-1.111
101	100	Unbiased	85.985	84.798	-1.187
102	0	Correlation	86.193	86.228	0.035
103	0	Correlation	86.088	86.119	0.031

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.088	86.141	86.193	0.074246	86.119	86.173	86.228	0.077075	0.031	0.033	0.035	0.0028284
50	85.979	86.139	86.329	0.15607	85.274	85.524	85.774	0.17737	-0.707	-0.61529	-0.555	0.056944
100	85.985	86.117	86.27	0.11619	84.644	84.901	85.109	0.17962	-1.346	-1.2155	-1.11	0.098527

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